Radiation Report

TPS7H5020-SEP and TPS7H5020-SP QMLP Neutron Displacement Damage (NDD) Characterization

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5020-SEP and TPS7H5020-SP QMLP device. The results show that all devices were fully functional and within production test limits after having been irradiated up to 1 × 10^{13} n/cm^2(1MeV(Si) equivalent). A sample size of twelve units were exposed per MIL-STD-883, Method 1017 for Neutron Irradiation, and an additional three devices were used as control units and were not irradiated. Electrical testing was performed at Texas Instruments before and after neutron irradiation using the production test program for TPS7H5020-SEP and TPS7H5020-SP QMLP.

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1 Overview

The TPS7H5020-SEP and TPS7H5020-SP QMLP is a radiation-hardness-assured, current mode, single-ended PWM controller with an integrated gate driver that can be utilized in both silicon and gallium nitride (GaN) power semiconductor based converter designs. The TPS7H5020 integrates several key functions, such as soft-start, enable, and adjustable slope compensation while maintaining a small package size. The controller also features a 0.6V ± 1% voltage reference tolerance to support highly accurate power converter designs. The TPS7H5020-SEP is packaged in a plastic 24-pin HTSSOP PWP package.

Table 1-1. Overview Information

TI Device	**TPS7H5020-SEP** **TPS7H5020-SP QMLP**
TI Part Number	TPS7H5020MPWPTSEP 5962R2420101PYE
VID Number	V62/25651
SMD Number	5962-24201
Device Function	PWM controller with an integrated gate driver
Technology	Linear BiCMOS 7 (LBC7)
Assembly Lot Number / Lot Trace Code	5020307 / 51AFNPK
Unbiased Quantity Tested	12
Exposure Facility	VPT Rad
Neutron Fluence (1-MeV equivalent)	1.0×10^{12}, 5.0×10^{12}, 1.0×10^{13} n/cm^2
Irradiation Temperature	Room temperature
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2 Test Procedures

The TPS7H5020-SEP and TPS7H5020-SP QMLP was electrically pre- and post-tested using the production automated test equipment program.

General test procedures adhered to MIL-STD-883, Method 1017 for Neutron Irradiation of TPS7H5020-SEP and TPS7H5020-SP QMLP. Neutron irradiation conditions are listed in Table 2-1.

Table 2-1. Neutron Irradiation Conditions

Group	Sample Quantity	Neutron Fluence (n/cm^2)	BIAS
A	4	1×10^{12}	Unbiased
B	4	5×10^{12}	Unbiased
C	4	1×10^{13}	Unbiased
Correlation	3	0	N/A

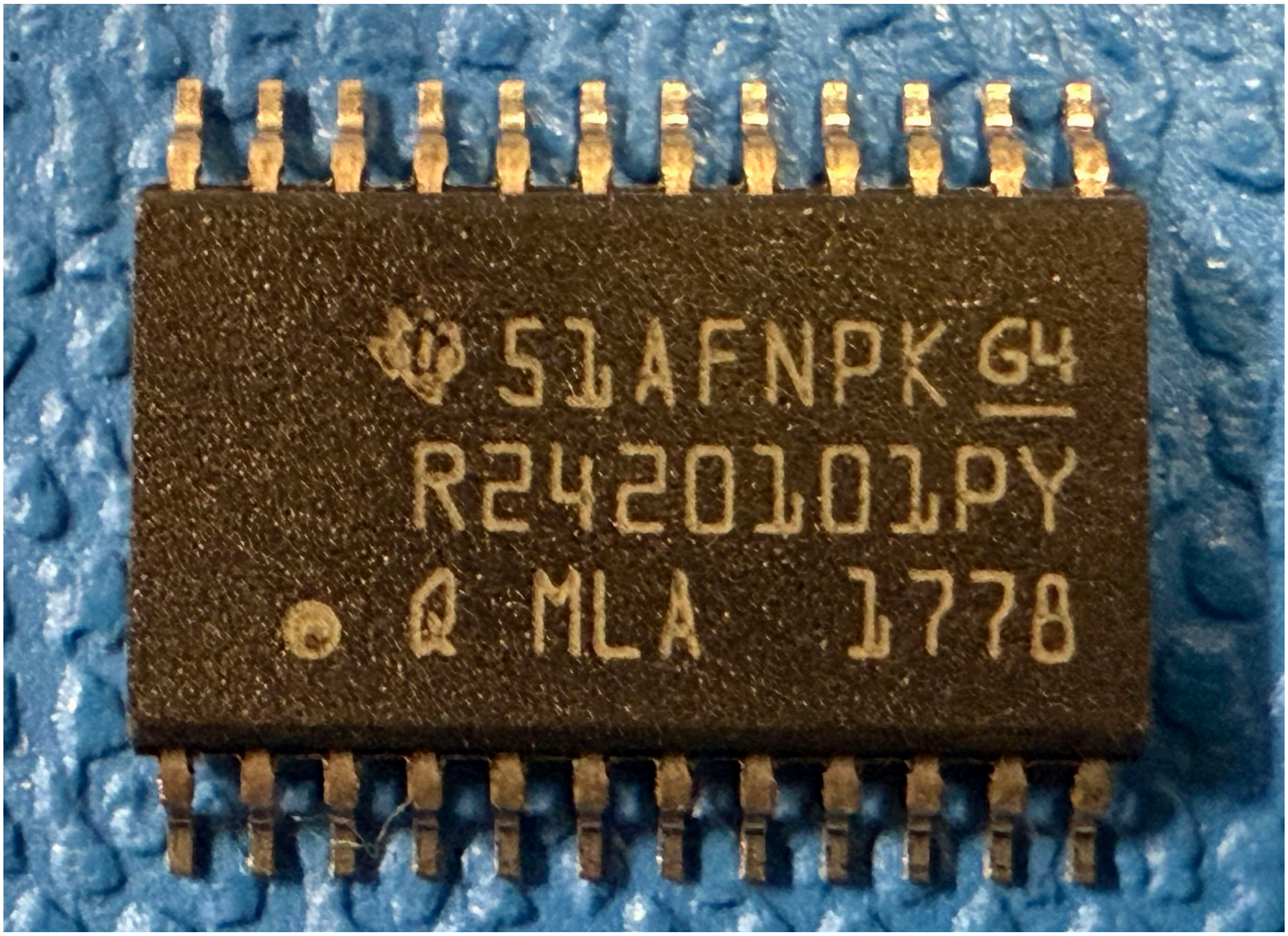


Figure 2-1. TPS7H5020-SP QMLP Device

3 Facility

VPT Rad performs all neutron displacement damage irradiations in a Low-Enriched, open-pool, water moderated, thermal neutron reactor. VPT Rad uses flat-plate type fuel, and having a maximum thermal energy output of up to 1MW. The Fast Neutron Irradiator (FNI) faces one side of the reactor core, the design produces a geometrical planar beam of fast neutrons that is approximately uniform over an area of 12in × 20in. Lead and thermal neutron absorbing compounds are combined to filter out both fission gammas and thermal neutrons. The ratio of fast-to-thermal neutrons is approximately 400:1, with a gamma exposure of less than 150rad (Si) for a 1E12 n/cm2 (1MeV Si equivalent) exposure. The FNI can accommodate a sample or samples with size up to 30cm in diameter and 15 cm thick including packaging materials. The minimum neutron fluence rate is 1E6 n/cm2-s. The maximum neutron fluence rate is approximately 1.0 E11 n/cm2-s. Both values are 1MeV Si equivalent.

The neutron fluence rate is determined using the previously measured neutron radiation field for the FNI, performed in accordance with ASTM standards (ASTM F1190), and correlated to the measured reactor power level. The neutron dose is timed to meet the customer-specified fluence for the irradiation. Neutron dosimetry meeting ASTM standards (ASTM E265) is used to track and verify irradiations meet the required minimum. The facility retains source-suitability with the Defense Logistics Agency (DLA) Laboratory Suitability Program for ASTM Test Method 1017. The DUTS are typically irradiation in an unbiased condition as per TM1017. If bias conditions are required, the conditions can be maintained through dry thimbles connected to the irradiation volume.

4 Results

There were no functional failures at any irradiation level. All parametric measurements remained well within all data sheet limits for all exposure levels. The full parameter list is shown in Section 4.1 and the related data can be found in Appendix A.

Specifications are at ambient temperature TA = 25°C, PVIN=VIN= 4.5V to 14V unless otherwise noted. Parameters not listed in the table are omitted either because there is no parametric data or because verification was done through bench testing. Parameters without MIN and MAX values are functionally assured by ATE testing.

4.1 Data Sheet Electrical Parameters and Associated Tests

Table 4-1. Electrical Characteristics Table

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
SUPPLY VOLTAGES AND CURRENTS							
IDD	Operating supply current	No load for OUT, PVIN = VIN	f_{SW} = 100kHz		11	mA	14.1, 14.2, 14.3, 14.4
			f_{SW} = 500kHz		17		14.6, 14.8, 14.10, 14.12
			f_{SW} = 1MHz		25		14.14, 14.15, 14.16, 14.17
		C_{LOAD} = 1000pF for OUT, PVIN = VIN	f_{SW} = 100kHz		12	mA	14.8, 14.19, 14.20, 14.21
			f_{SW} = 500kHz		22		14.22, 14.23, 14.24, 14.25
			f_{SW} = 1MHz		28		14.26, 14.27, 14.28, 14.29
		C_{LOAD} = 1000pF for OUT, VIN = 12V, PVIN = VLDO = 5V	f_{SW} = 100kHz		10	mA	14.3
			f_{SW} = 500kHz		13		14.31
			f_{SW} = 1MHz		20		14.32
I_{start}	Startup Current	VIN = 3.5V			5	mA	14.5
IDD(dis)	Standby current	EN = 0V			8	mA	14.7, 14.9, 14.11, 14.13
VLDO	Internal linear regulator output voltage	C_{VLDO} = 1µF	5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.74kΩ	4.36	4.62	V	15.1, 15.4, 15.5
			5.5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.24kΩ	4.84	5.14		15.8, 15.11, 15.12
			6V ≤ VIN ≤ 14V, RVT = 10 kΩ, RVB = 2.87kΩ	5.31	5.65		15.15, 15.18, 15.19
VLDO_DO	Internal linear dropout voltage	I_{VLDO} = 25mA, C_{VLDO} = 1µF			0.4	V	15.40, 15.41, 15.42, 15.43, 15.44, 15.45

Table 4-1. Electrical Characteristics Table (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
I_VLDO	Maximum VLDO output current	VLDO ≥ 96% of VLDO at no load, C_{VLDO} = 1µF	VIN = VLDO + 0.5V	25		mA	15.2, 15.3, 15.9, 15.10, 15.16, 15.17
			VIN = VLDO + 1V	55			15.28, 15.29, 15.30, 15.34, 15.35, 15.36
			VIN ≥ 7V	90			15.6, 15.7, 15.13, 15.14, 15.20, 15.21, 15.31, 15.32, 15.33, 15.37, 15.38, 15.39
ENABLE AND UNDERVOLTAGE LOCKOUT							
V_{ENR}	Enable rising threshold			0.57	0.66	V	16.1, 16.4, 16.7, 16.10
V_{ENF}	Enable falling threshold			0.48	0.55	V	16.2, 16.5, 16.8, 16.11
I_{EN}	Enable input leakage current	VIN = 14V	EN = 1V		100	nA	16.15, 16.17
			EN = 7V		700		16.16, 16.18
$PVIN_{UVLOR}$	PVIN UVLO rising			3.65	3.95	V	17.1, 17.10, 17.19
$PVIN_{UVLOF}$	PVIN UVLO falling			3.45	3.75	V	17.2, 17.11, 17.20
VIN_{UVLOR}	VIN UVLO rising			3.85	4.15	V	17.4, 17.13, 17.22
VIN_{UVLOF}	VIN UVLO falling			3.65	3.95	V	17.5, 17.14, 17.23
$VLDO_{UVLOR}$	VLDO UVLO rising			3.65	3.95	V	17.7, 17.16, 17.25
$VLDO_{UVLOF}$	VLDO UVLO falling			3.45	3.75	V	17.8, 17.17, 17.26
SOFT START							
I_{SS}	Soft-start current	SS = 0.3V		2	3.4	µA	18.1, 18.5, 18.9, 18.13, 18.17, 18.21, 18.25, 18.29, 18.33, 18.37, 18.41, 18.45
ERROR AMPLIFIER							
EA_{gm}	Error amplifier transconductance	–10µA < I_{COMP} < 10µA, $V_{(COMP)}$ = 1V		1100	2700	µA/V	19.1, 19.5, 19.9, 19.13
EA_{ISRC}	Error amplifier source current	$V_{(COMP)}$ = 1V, 100mV input overdrive		95	210	µA	19.2, 19.6, 19.10, 19.14
EA_{ISNK}	Error amplifier sink current	$V_{(COMP)}$ = 1V, 100mV input overdrive		95	210	µA	19.3, 19.7, 19.11, 19.15

Table 4-1. Electrical Characteristics Table (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
EA_{OS}	Error amplifier input offset voltage			-5	6	mV	19.27, 19.30, 19.33, 19.36, 19.39, 19.42, 19.45, 19.48, 19.51, 19.54, 19.57, 19.60
EA_{IB}	Error amplifier input bias current				25	nA	19.4, 19.8, 19.12, 19.16, 19.17, 19.18, 19.19, 19.20, 19.21, 19.22, 19.23, 19.24
OSCILLATOR							
$SYNC_{IL}$	SYNC in low-level	VLDO = 4.5V	VIN < 5V		0.8	V	20.1
			VIN ≥ 5V		0.8		20.3, 20.5, 20.7
		VLDO = 5.5V	VIN < 6V		0.8	V	20.9
			VIN ≥ 6V		0.8		20.11, 20.13
$SYNC_{IH}$	SYNC in high-level	VLDO = 4.5V	VIN < 5V	3.5		V	20.2, 20.4
			VIN ≥ 5V	3.5			20.6, 20.8
		VLDO = 5.5V	VIN < 6V	3.5		V	20.1
			VIN ≥ 6V	3.5			20.12, 20.14,
f_{SYNC}	SYNC in frequency range			100	1000	kHz	20.16, 20.20, 20.24, 20.28, 20.32, 20.34, 20.36, 20.38, 20.40, 20.44, 20.48, 20.52, 20.56, 20.60, 20.64, 20.68, 20.72, 20.74, 20.76, 20.78, 20.80, 20.82, 20.84, 20.86, 20.88, 20.90, 20.92, 20.94, 20.96, 20.98, 20.100, 20.102

Table 4-1. Electrical Characteristics Table (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
f_{SW}	RT programmed switching frequency	RT = 1.18MΩ		80	110	kHz	20.15, 20.19, 20.23, 20.27, 20.71, 20.73, 20.75, 20.77
		RT = 560kΩ		175	220	kHz	20.31, 20.33, 20.35, 20.37, 20.79, 20.81, 20.83, 20.85
		RT = 210kΩ		450	550	kHz	20.39, 20.43, 20.47, 20.51, 20.87, 20.89, 20.91, 20.93
		RT = 100kΩ		925	1100	kHz	20.55, 20.59, 20.63, 20.67, 20.95, 20.97, 20.99, 20.101
VOLTAGE REFERENCE							
VREF	Internal voltage reference	Measured at COMP, COMP = VSENSE	TA = 25°C	0.597	0.603	V	19.25, 19.28, 19.31, 19.34, 19.37, 19.40, 19.43, 19.46, 19.49, 19.52, 19.55, 19.58, 19.61, 19.63, 19.65, 19.67, 19.69, 19.71, 19.73, 19.75, 19.77, 19.79, 19.81, 19.83
REFCAP	REFCAP voltage	C_{REFCAP} = 470nF		1.208	1.235	V	21.1, 21.3, 21.5, 21.7, 21.9, 21.11, 21.13, 21.15, 21.17, 21.19, 21.21, 21.23, 21.25, 21.27, 21.29, 21.31, 21.33, 21.35, 21.37, 21.39, 21.41, 21.43, 21.45, 21.47
CURRENT SENSE							
CCSR	COMP to CS_ILIM ratio	RSC = open		1.94	2.06		28.1, 28.2, 28.3, 28.4
V_{CS_ILIM}	Current limit (overcurrent) threshold			0.96	1.04	V	28.9, 28.10, 28.11, 28.12, 28.13, 28.14, 28.15, 28.16, 28.17, 28.18, 28.19, 28.20

Table 4-1. Electrical Characteristics Table (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
	CS_ILIM to OUT delay	CS_ILIM = 1V to 90% of OUT falling			115	ns	28.21, 28.22, 28.23, 28.24, 28.25, 28.26, 28.27, 28.28, 28.29, 28.30, 28.31, 28.32, 28.33, 28.34, 28.35, 28.36, 28.37, 28.38, 28.39, 28.40, 28.41, 28.42, 28.43, 28.44
GATE DRIVER							
V_{OL}	Low-level voltage	I_{OL} = 50mA			0.15	V	24.1, 24.3, 24.5, 24.7
PVIN - V_{OH}	High-level voltage	I_{OH} = 50mA			0.25	V	24.2, 24.4, 24.6, 24.8
t_{R_OUT}	OUT rise time	C_{LOAD} = 1000pF, 10% to 90%	VIN = PVIN = 4.5V		14	ns	24.9
			VIN = PVIN = 5V		14		24.11
			VIN = PVIN = 12V		18		24.13
			VIN = PVIN = 14V		20		24.15
			VIN = 12V, PVIN = VLDO		16		24.17, 24.19, 24.21
		C_{LOAD} = 220pF, 10% to 90%	VIN = 12V, PVIN = VLDO		12		24.23, 24.25, 24.27
t_{F_OUT}	OUT fall time	C_{LOAD} = 1000pF, 90% to 10%	VIN = PVIN = 4.5V		14	ns	24.1
			VIN = PVIN = 5V		14		24.12
			VIN = PVIN = 12V		18		24.14
			VIN = PVIN = 14V		18		24.16
			VIN = 12V, PVIN = VLDO		14		24.18, 24.20, 24.22
		C_{LOAD} = 220pF, 90% to 10%	VIN = 12V, PVIN = VLDO		10		24.24, 24.26, 24.28
R_{OH}	Pull-up resistance	100mA from OUT			4.7	Ω	23.5, 23.7, 23.9, 23.11
R_{OL}	Pull-down resistance	100mA into OUT			2.8	Ω	23.6, 23.8, 23.10, 23.12
V_{UCLAMP}	Unpowered OUT clamp voltage	Switching disabled, SYS_ON = 0 1mA pull-up applied to OUT	PVIN = 0V		1	V	24.29
			0V < PVIN < 5V		2.5		24.3
PWM AND DUTY CYCLE							
TLEB	Leading edge blank time	5V ≤ VIN ≤ 14V, 10% of OUT rising to end of blanking			80	ns	25.1, 25.4, 25.7

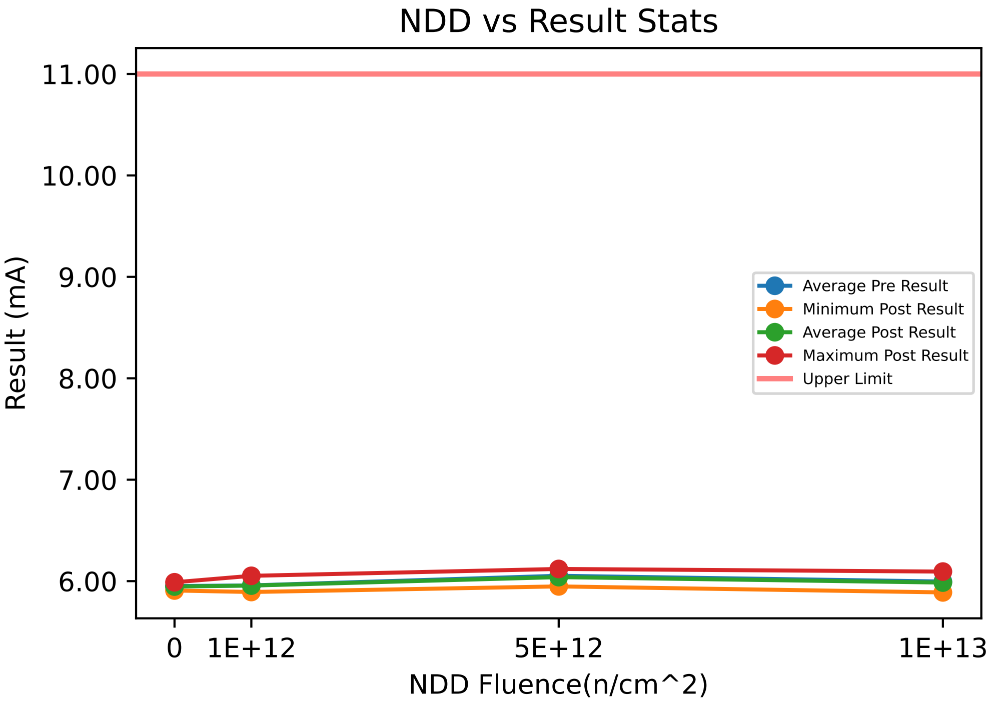
Table 4-1. Electrical Characteristics Table (continued)

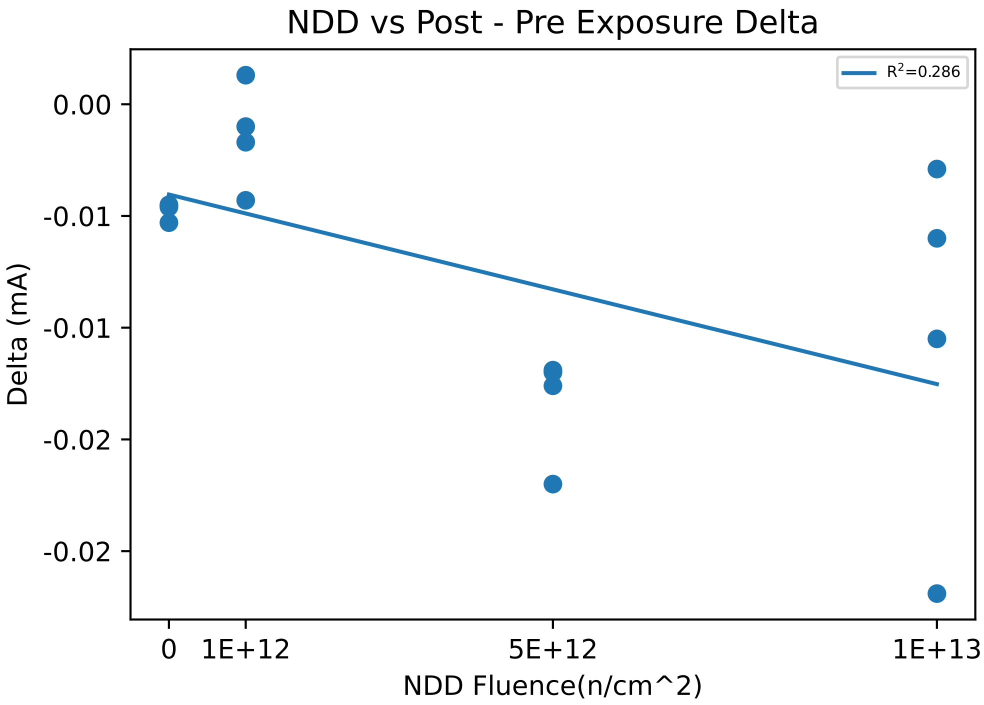
PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT	Test #
t_{on_min}	Minimum on-time			165	ns	26.1, 26.2, 26.3, 26.4
t_{off_min}	Minimum off-time pulse extender			70	ns	26.5, 26.7

A Appendix: NDD Report Data

This appendix contains the detailed NDD test results.

Device Test: 14.1 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/100kHz//@IDD_ACT_100K_NOLOAD





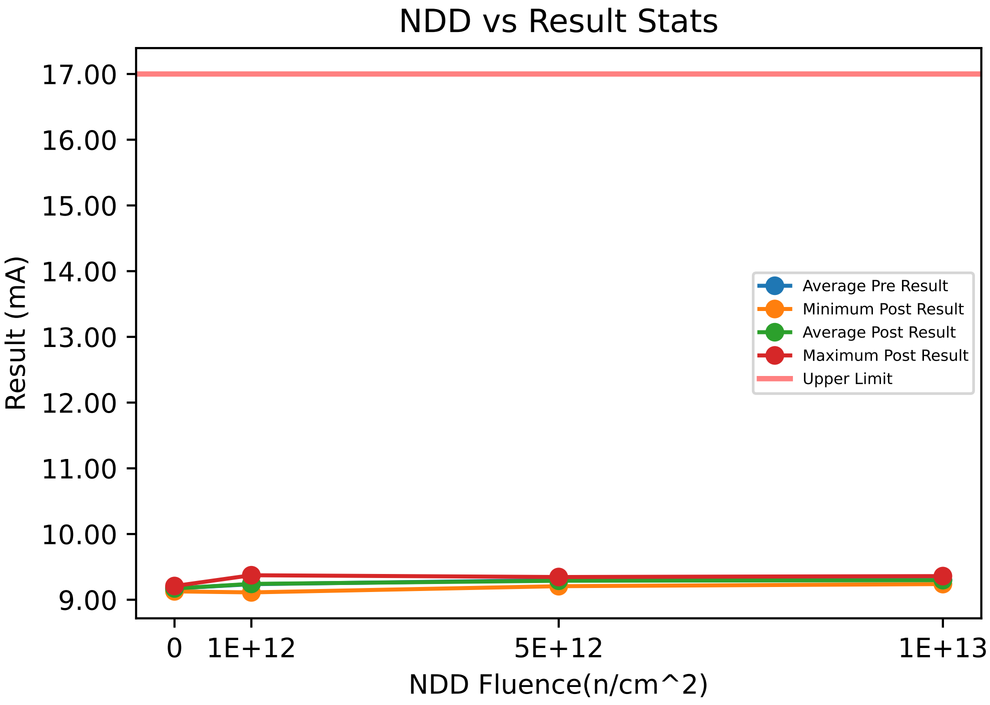
Test Results (Upper Limit = 11.0 (mA))

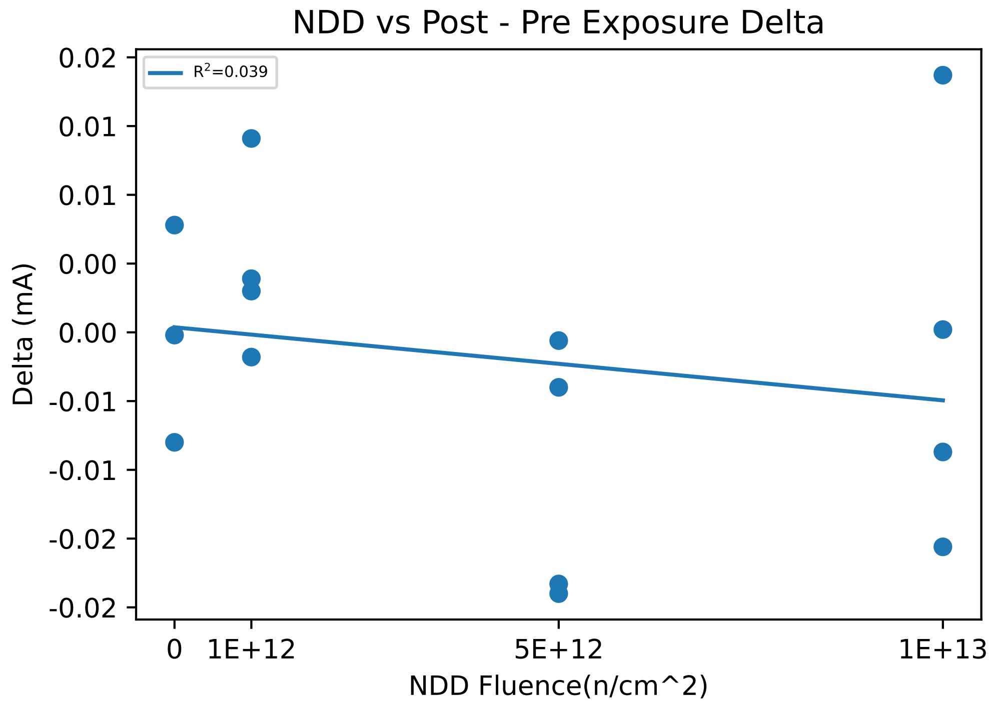
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.9307	5.9264	-0.0043
2	1e+12	NDD	5.8916	5.8929	0.0013
3	1e+12	NDD	6.0534	6.0524	-0.001
4	1e+12	NDD	5.955	5.9533	-0.0017
5	5e+12	NDD	6.1321	6.1202	-0.0119
6	5e+12	NDD	6.0784	6.0614	-0.017
7	5e+12	NDD	6.0414	6.0288	-0.0126
8	5e+12	NDD	5.9601	5.9481	-0.012
9	1e+13	NDD	5.9196	5.9167	-0.0029
10	1e+13	NDD	5.895	5.889	-0.006
11	1e+13	NDD	6.0543	6.0438	-0.0105
12	1e+13	NDD	6.1162	6.0943	-0.0219
13	0	CORRELATION	5.9482	5.9437	-0.0045
14	0	CORRELATION	5.9934	5.9888	-0.0046
15	0	CORRELATION	5.913	5.9077	-0.0053

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.913	5.9515	5.9934	0.040304	5.9077	5.9467	5.9888	0.040635	-0.0053	-0.0048	-0.0045	0.00043589
1e+12	5.8916	5.9577	6.0534	0.068954	5.8929	5.9562	6.0524	0.068697	-0.0043	-0.001425	0.0013	0.0023056
5e+12	5.9601	6.053	6.1321	0.072266	5.9481	6.0396	6.1202	0.071788	-0.017	-0.013375	-0.0119	0.0024364
1e+13	5.895	5.9963	6.1162	0.10628	5.889	5.9859	6.0943	0.098795	-0.0219	-0.010325	-0.0029	0.0083236

Device Test: 14.10 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

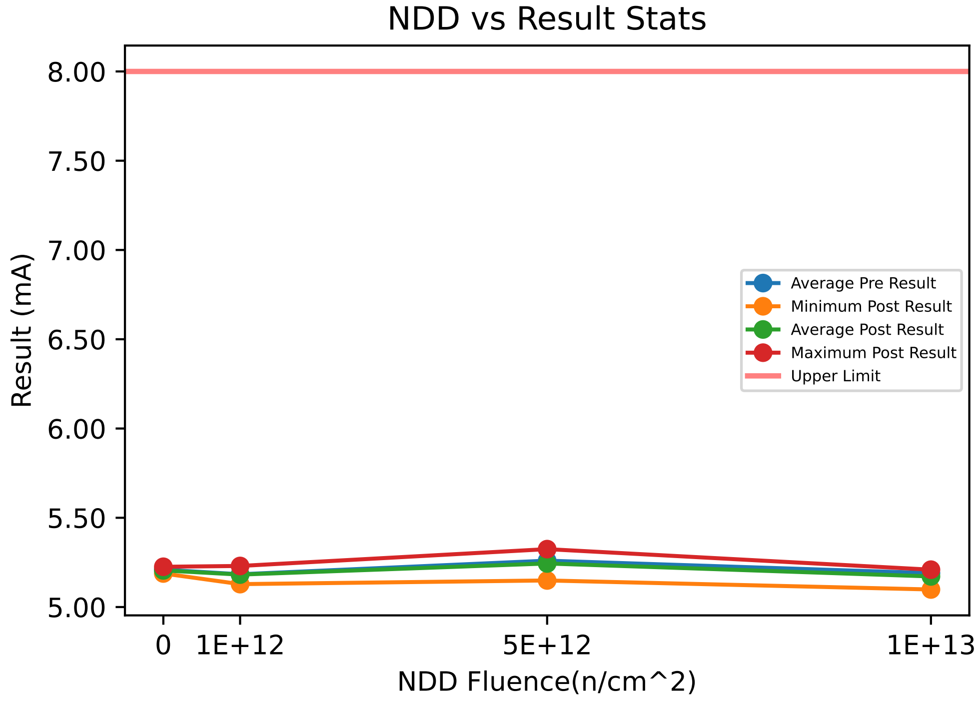
Test Results (Upper Limit = 17.0 (mA))

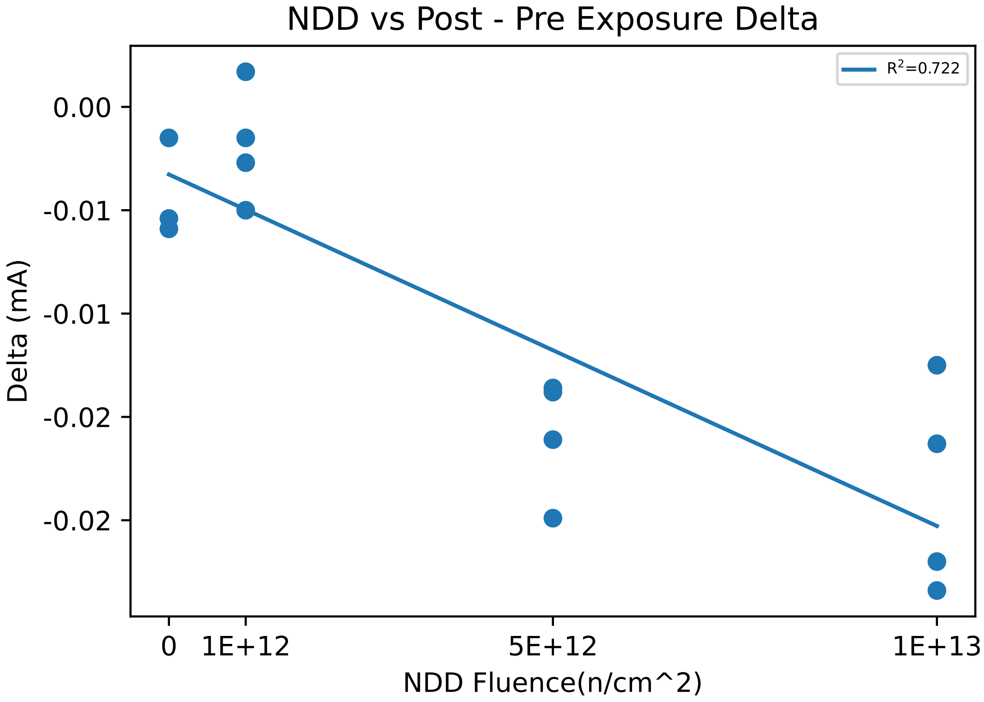
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.1997	9.1979	-0.0018
2	1e+12	NDD	9.1089	9.1119	0.003
3	1e+12	NDD	9.3588	9.3729	0.0141
4	1e+12	NDD	9.2794	9.2833	0.0039
5	5e+12	NDD	9.3446	9.3263	-0.0183
6	5e+12	NDD	9.3466	9.346	-0.0006
7	5e+12	NDD	9.2809	9.2769	-0.004
8	5e+12	NDD	9.2252	9.2062	-0.019
9	1e+13	NDD	9.2198	9.2385	0.0187
10	1e+13	NDD	9.2842	9.2844	0.0002
11	1e+13	NDD	9.325	9.3094	-0.0156
12	1e+13	NDD	9.3686	9.3599	-0.0087
13	0	CORRELATION	9.2092	9.209	-0.0002
14	0	CORRELATION	9.1866	9.1786	-0.008
15	0	CORRELATION	9.1197	9.1275	0.0078

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.1197	9.1718	9.2092	0.046541	9.1275	9.1717	9.209	0.041186	-0.008	-0.00013333	0.0078	0.0079002
1e+12	9.1089	9.2367	9.3588	0.10713	9.1119	9.2415	9.3729	0.11212	-0.0018	0.0048	0.0141	0.0066858
5e+12	9.2252	9.2993	9.3466	0.058077	9.2062	9.2889	9.346	0.062296	-0.019	-0.010475	-0.0006	0.0095455
1e+13	9.2198	9.2994	9.3686	0.063275	9.2385	9.298	9.3599	0.050619	-0.0156	-0.00135	0.0187	0.014849

Device Test: 14.11 IDD_DIS|STANDBY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_DIS





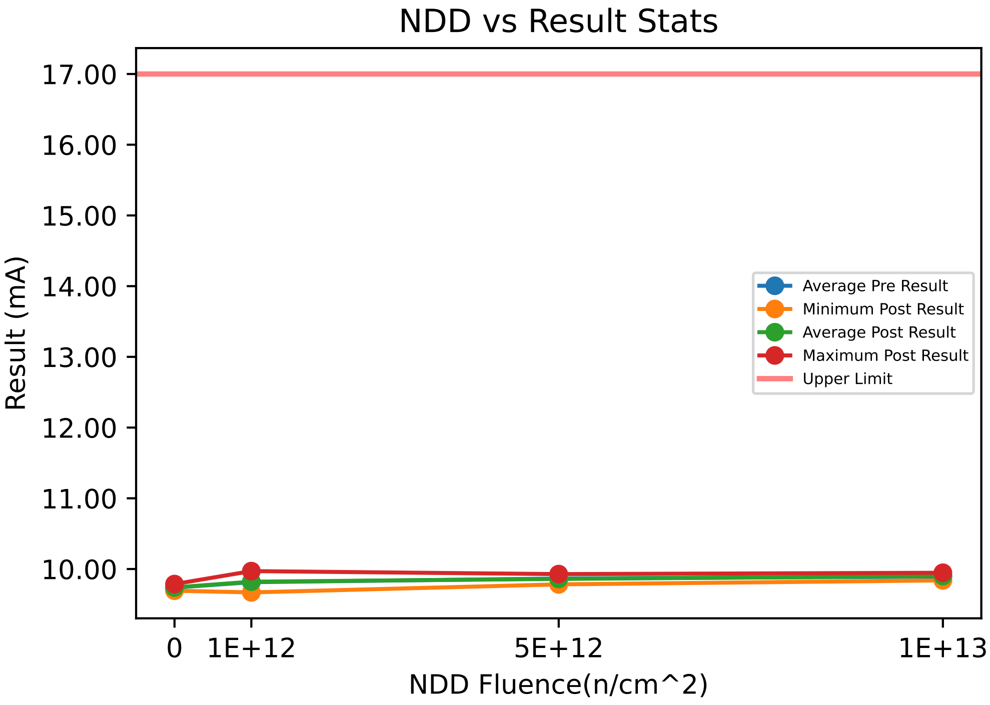
Test Results (Upper Limit = 8.0 (mA))

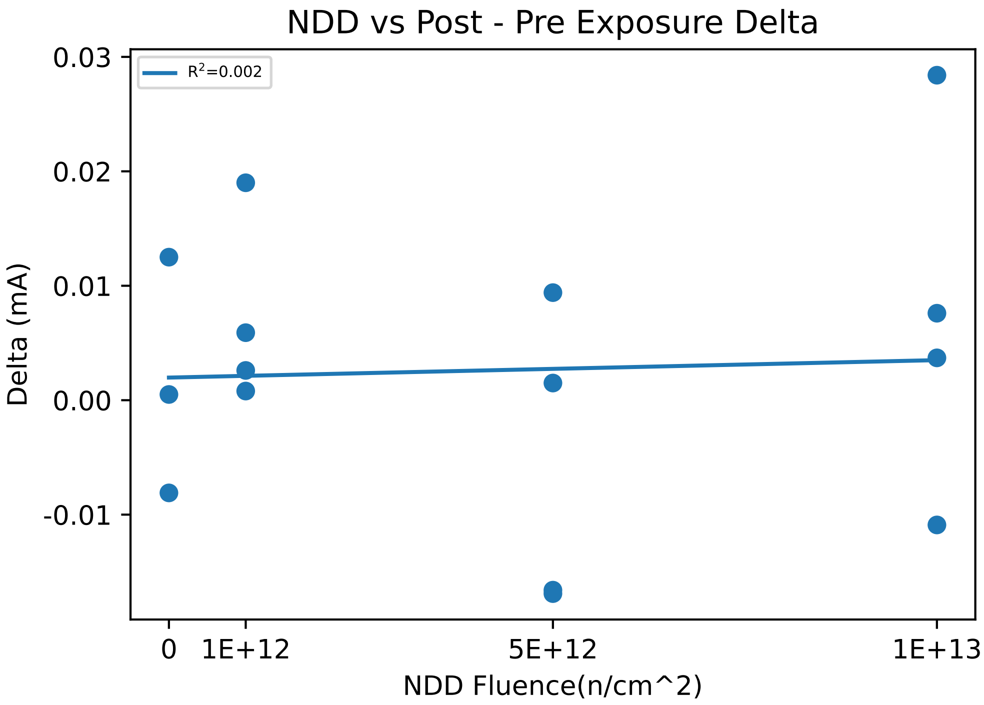
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.1311	5.1284	-0.0027
2	1e+12	NDD	5.1622	5.1607	-0.0015
3	1e+12	NDD	5.2351	5.2301	-0.005
4	1e+12	NDD	5.2061	5.2078	0.0017
5	5e+12	NDD	5.3405	5.3244	-0.0161
6	5e+12	NDD	5.2695	5.2557	-0.0138
7	5e+12	NDD	5.2607	5.2471	-0.0136
8	5e+12	NDD	5.1688	5.1489	-0.0199
9	1e+13	NDD	5.1886	5.1723	-0.0163
10	1e+13	NDD	5.1109	5.0984	-0.0125
11	1e+13	NDD	5.2293	5.2059	-0.0234
12	1e+13	NDD	5.2313	5.2093	-0.022
13	0	CORRELATION	5.2033	5.2018	-0.0015
14	0	CORRELATION	5.231	5.2256	-0.0054
15	0	CORRELATION	5.1938	5.1879	-0.0059

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1938	5.2094	5.231	0.019328	5.1879	5.2051	5.2256	0.019065	-0.0059	-0.0042667	-0.0015	0.002409
1e+12	5.1311	5.1836	5.2351	0.046089	5.1284	5.1818	5.2301	0.045846	-0.005	-0.001875	0.0017	0.0027909
5e+12	5.1688	5.2599	5.3405	0.070447	5.1489	5.244	5.3244	0.072237	-0.0199	-0.01585	-0.0136	0.0029286
1e+13	5.1109	5.19	5.2313	0.0563	5.0984	5.1715	5.2093	0.051499	-0.0234	-0.01855	-0.0125	0.0050692

Device Test: 14.12 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

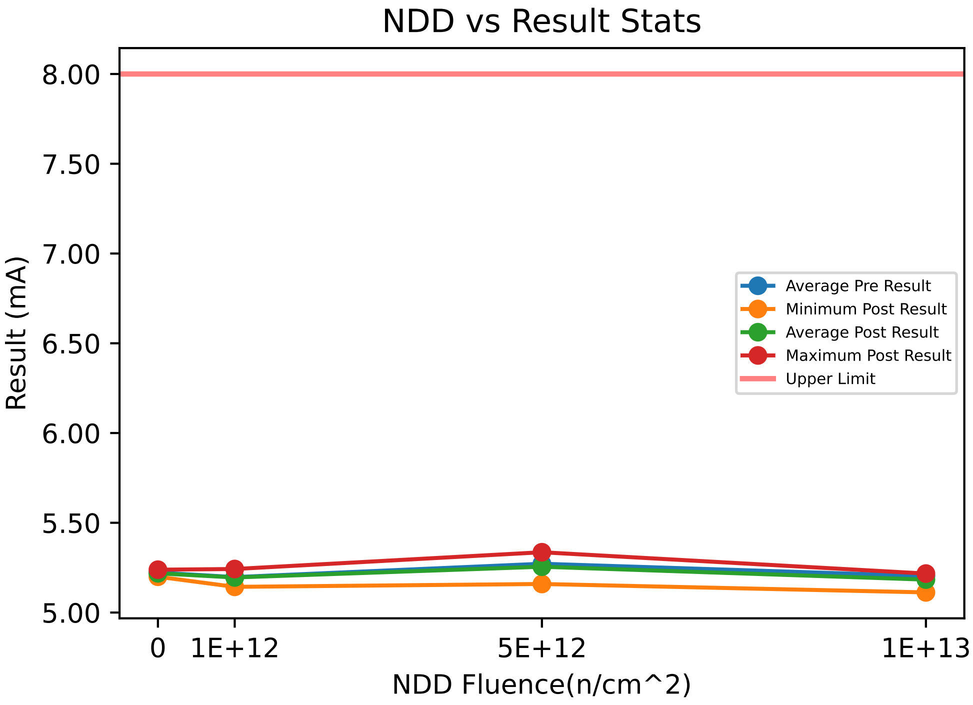
Test Results (Upper Limit = 17.0 (mA))

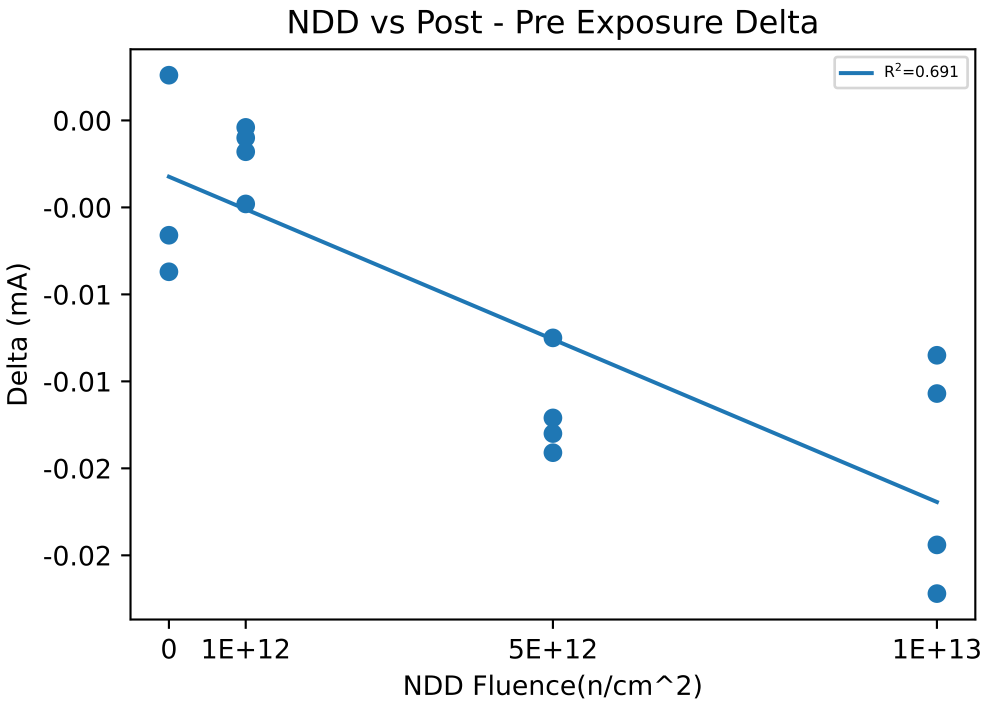
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.7633	9.7641	0.0008
2	1e+12	NDD	9.6667	9.6693	0.0026
3	1e+12	NDD	9.9513	9.9703	0.019
4	1e+12	NDD	9.8738	9.8797	0.0059
5	5e+12	NDD	9.9001	9.8832	-0.0169
6	5e+12	NDD	9.9186	9.928	0.0094
7	5e+12	NDD	9.8439	9.8454	0.0015
8	5e+12	NDD	9.7993	9.7827	-0.0166
9	1e+13	NDD	9.8109	9.8393	0.0284
10	1e+13	NDD	9.9045	9.9121	0.0076
11	1e+13	NDD	9.915	9.9041	-0.0109
12	1e+13	NDD	9.9432	9.9469	0.0037
13	0	CORRELATION	9.7865	9.787	0.0005
14	0	CORRELATION	9.7449	9.7368	-0.0081
15	0	CORRELATION	9.6807	9.6932	0.0125

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.6807	9.7374	9.7865	0.053301	9.6932	9.739	9.787	0.046939	-0.0081	0.0016333	0.0125	0.010347
1e+12	9.6667	9.8138	9.9513	0.12476	9.6693	9.8209	9.9703	0.13164	0.0008	0.007075	0.019	0.0082257
5e+12	9.7993	9.8655	9.9186	0.054362	9.7827	9.8598	9.928	0.06151	-0.0169	-0.00565	0.0094	0.013217
1e+13	9.8109	9.8934	9.9432	0.057376	9.8393	9.9006	9.9469	0.044892	-0.0109	0.0072	0.0284	0.016222

Device Test: 14.13 IDD_DIS|STANDBY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_DIS





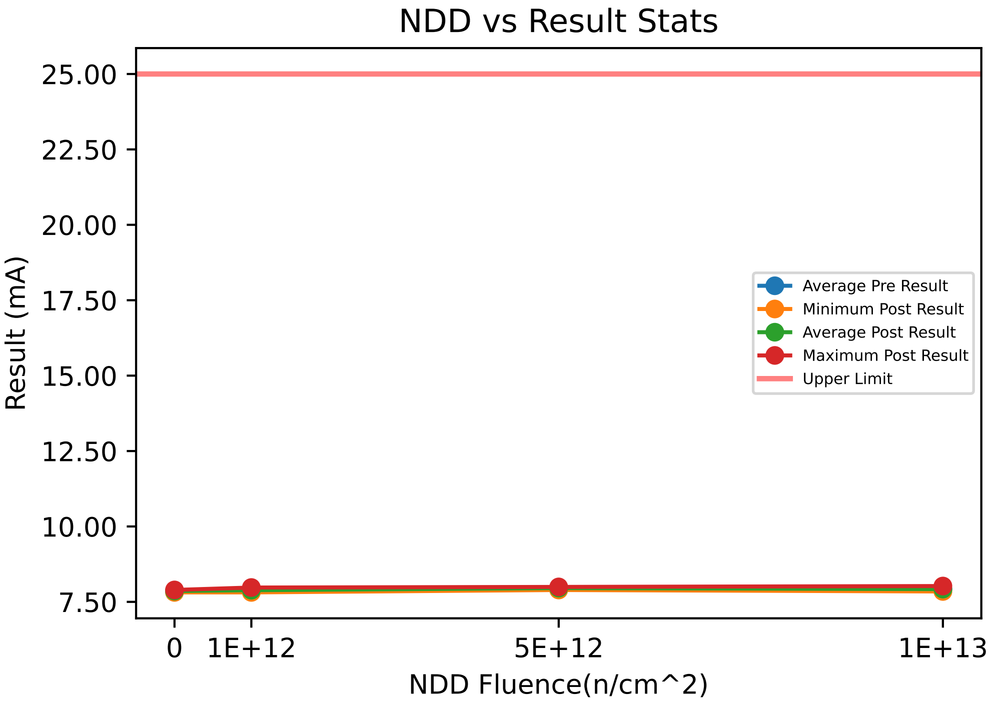
Test Results (Upper Limit = 8.0 (mA))

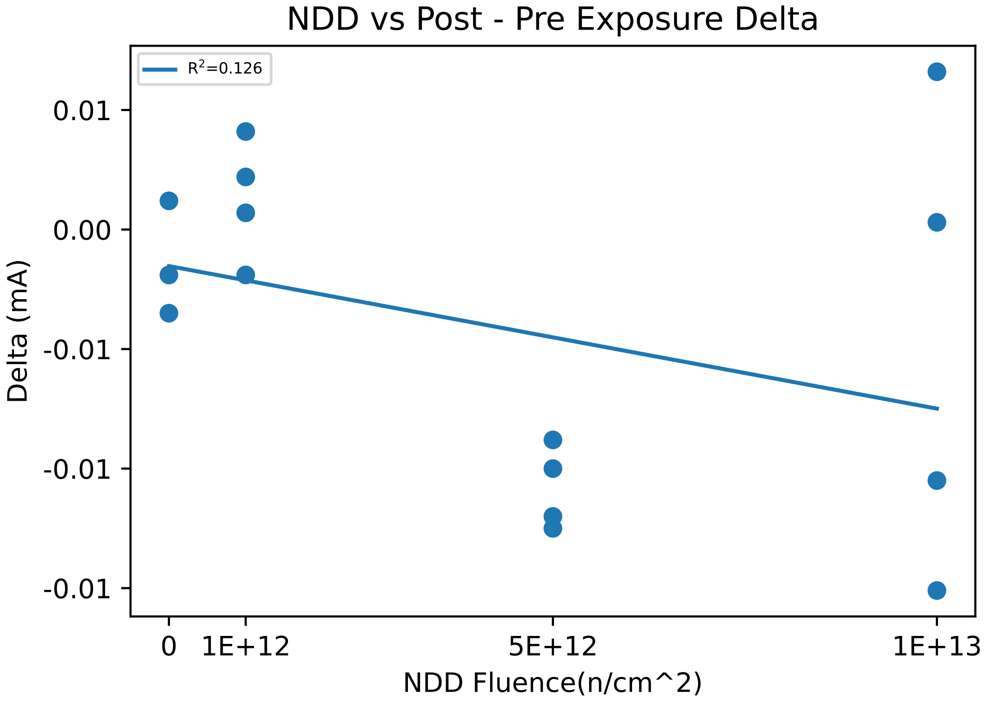
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.1441	5.1431	-0.001
2	1e+12	NDD	5.1739	5.1735	-0.0004
3	1e+12	NDD	5.2473	5.2425	-0.0048
4	1e+12	NDD	5.2242	5.2224	-0.0018
5	5e+12	NDD	5.353	5.3359	-0.0171
6	5e+12	NDD	5.284	5.266	-0.018
7	5e+12	NDD	5.2721	5.2596	-0.0125
8	5e+12	NDD	5.1782	5.1591	-0.0191
9	1e+13	NDD	5.2034	5.1877	-0.0157
10	1e+13	NDD	5.1257	5.1122	-0.0135
11	1e+13	NDD	5.2437	5.2165	-0.0272
12	1e+13	NDD	5.2415	5.2171	-0.0244
13	0	CORRELATION	5.2146	5.2172	0.0026
14	0	CORRELATION	5.2474	5.2387	-0.0087
15	0	CORRELATION	5.206	5.1994	-0.0066

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.206	5.2227	5.2474	0.021847	5.1994	5.2184	5.2387	0.019679	-0.0087	-0.0042333	0.0026	0.0060103
1e+12	5.1441	5.1974	5.2473	0.046909	5.1431	5.1954	5.2425	0.045322	-0.0048	-0.002	-0.0004	0.0019528
5e+12	5.1782	5.2718	5.353	0.071887	5.1591	5.2551	5.3359	0.072764	-0.0191	-0.016675	-0.0125	0.002901
1e+13	5.1257	5.2036	5.2437	0.055115	5.1122	5.1834	5.2171	0.049394	-0.0272	-0.0202	-0.0135	0.0066277

Device Test: 14.14 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/1MHz//@IDD_ACT_1M_NOLOAD





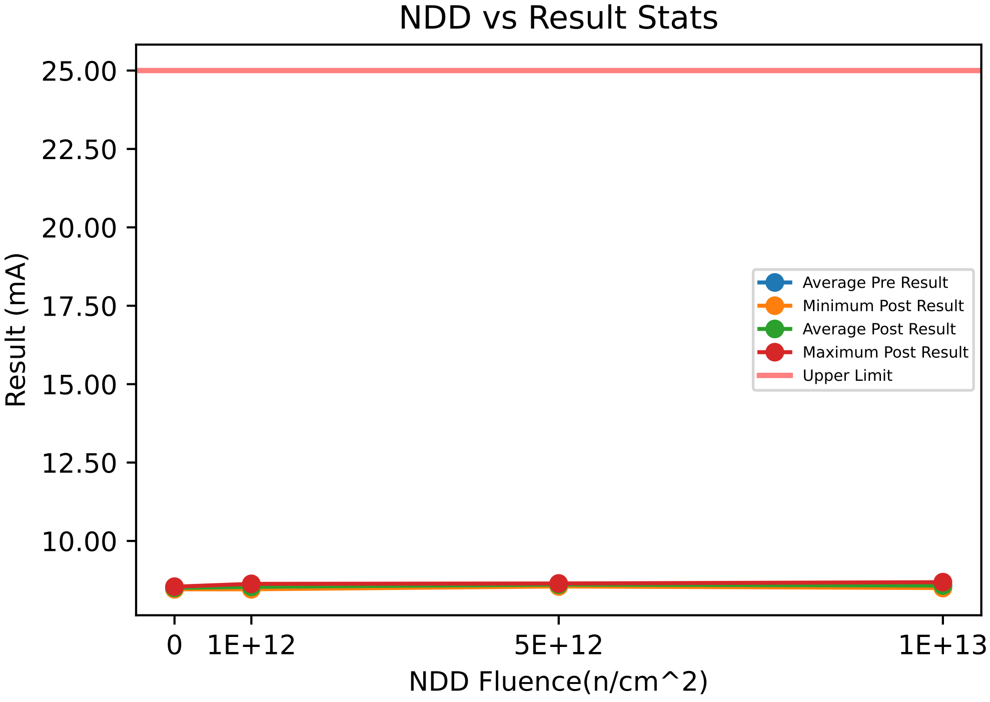
Test Results (Upper Limit = 25.0 (mA))

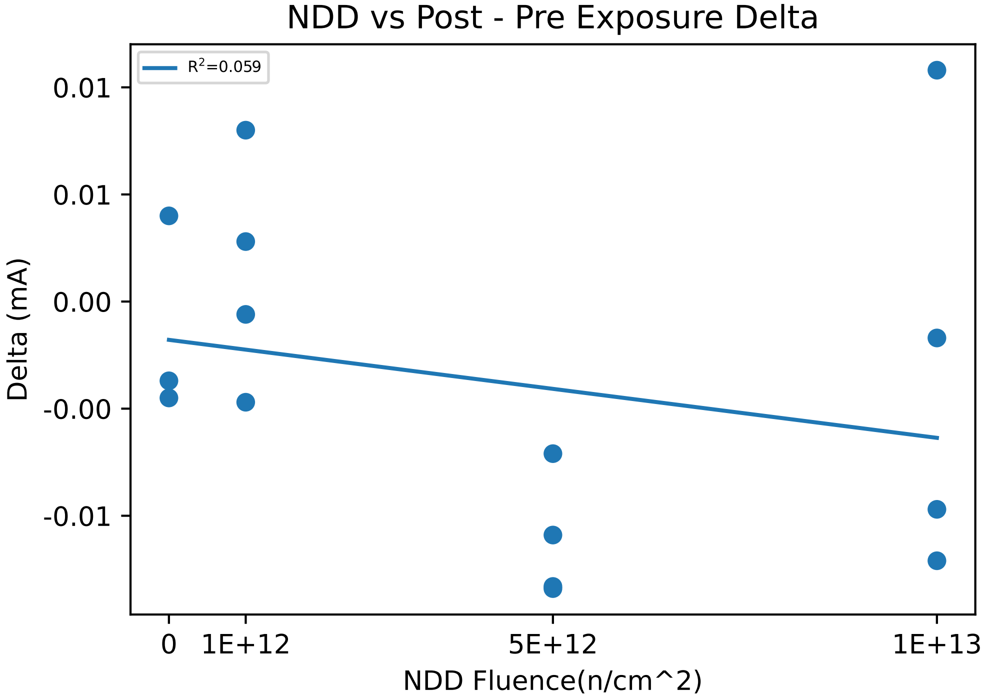
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.8704	7.8685	-0.0019
2	1e+12	NDD	7.8118	7.814	0.0022
3	1e+12	NDD	7.9715	7.9756	0.0041
4	1e+12	NDD	7.8863	7.887	0.0007
5	5e+12	NDD	8.0081	7.9956	-0.0125
6	5e+12	NDD	7.9976	7.9876	-0.01
7	5e+12	NDD	7.9539	7.9451	-0.0088
8	5e+12	NDD	7.9054	7.8934	-0.012
9	1e+13	NDD	7.8474	7.854	0.0066
10	1e+13	NDD	7.8443	7.8446	0.0003
11	1e+13	NDD	7.9753	7.9648	-0.0105
12	1e+13	NDD	8.0399	8.0248	-0.0151
13	0	CORRELATION	7.869	7.8671	-0.0019
14	0	CORRELATION	7.899	7.8955	-0.0035
15	0	CORRELATION	7.8131	7.8143	0.0012

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.8131	7.8604	7.899	0.043596	7.8143	7.859	7.8955	0.041206	-0.0035	-0.0014	0.0012	0.0023896
1e+12	7.8118	7.885	7.9715	0.065968	7.814	7.8863	7.9756	0.067129	-0.0019	0.001275	0.0041	0.0025329
5e+12	7.9054	7.9663	8.0081	0.046867	7.8934	7.9554	7.9956	0.046915	-0.0125	-0.010825	-0.0088	0.0017289
1e+13	7.8443	7.9267	8.0399	0.097047	7.8446	7.9221	8.0248	0.087587	-0.0151	-0.004675	0.0066	0.0099077

Device Test: 14.15 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





Test Results (Upper Limit = 25.0 (mA))

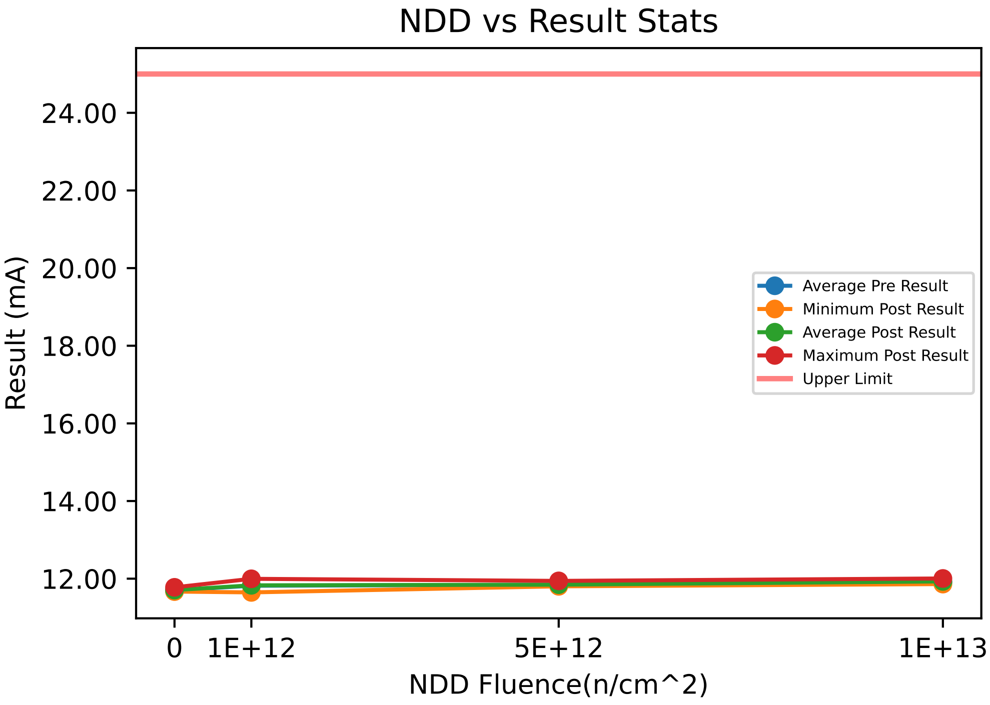
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.5234	8.5187	-0.0047
2	1e+12	NDD	8.4556	8.4584	0.0028
3	1e+12	NDD	8.6239	8.6319	0.008
4	1e+12	NDD	8.5382	8.5376	-0.0006
5	5e+12	NDD	8.6577	8.6444	-0.0133
6	5e+12	NDD	8.649	8.6419	-0.0071
7	5e+12	NDD	8.6056	8.5947	-0.0109
8	5e+12	NDD	8.5622	8.5488	-0.0134
9	1e+13	NDD	8.4965	8.5073	0.0108
10	1e+13	NDD	8.4996	8.4979	-0.0017
11	1e+13	NDD	8.6302	8.6205	-0.0097
12	1e+13	NDD	8.6977	8.6856	-0.0121
13	0	CORRELATION	8.515	8.5105	-0.0045
14	0	CORRELATION	8.5456	8.5419	-0.0037
15	0	CORRELATION	8.4539	8.4579	0.004

Test Statistics (mA)

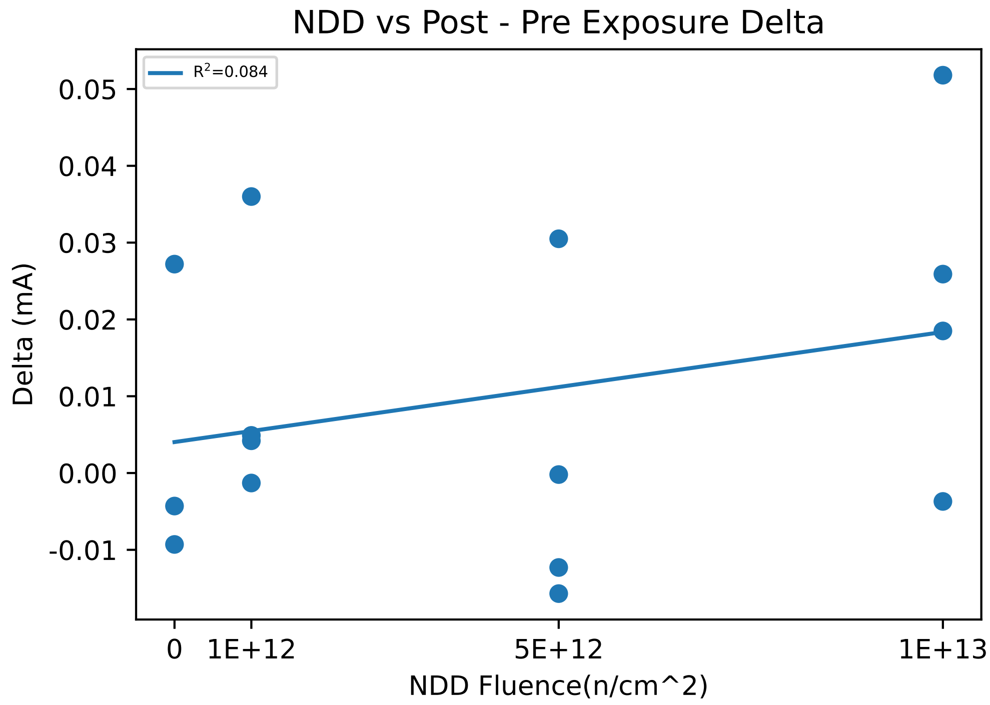
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.4539	8.5048	8.5456	0.046688	8.4579	8.5034	8.5419	0.042444	-0.0045	-0.0014	0.004	0.0046936
1e+12	8.4556	8.5353	8.6239	0.069167	8.4584	8.5366	8.6319	0.071923	-0.0047	0.001375	0.008	0.0053767
5e+12	8.5622	8.6186	8.6577	0.043981	8.5488	8.6075	8.6444	0.045293	-0.0134	-0.011175	-0.0071	0.0029523
1e+13	8.4965	8.581	8.6977	0.099676	8.4979	8.5778	8.6856	0.090918	-0.0121	-0.003175	0.0108	0.010323

Device Test: 14.16 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



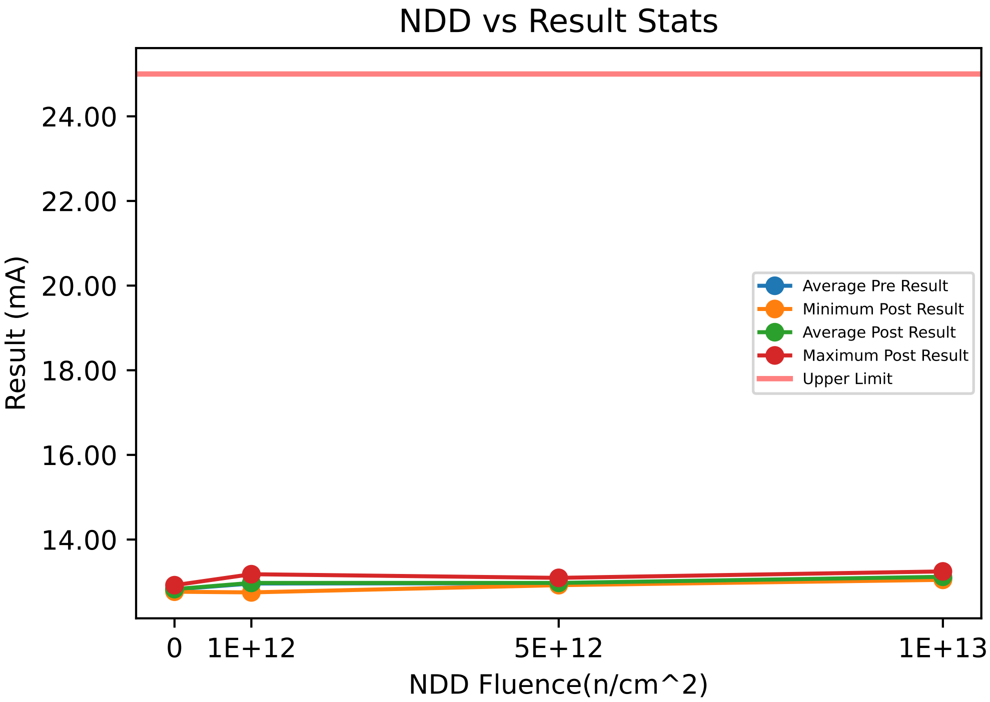
Test Results (Upper Limit = 25.0 (mA))

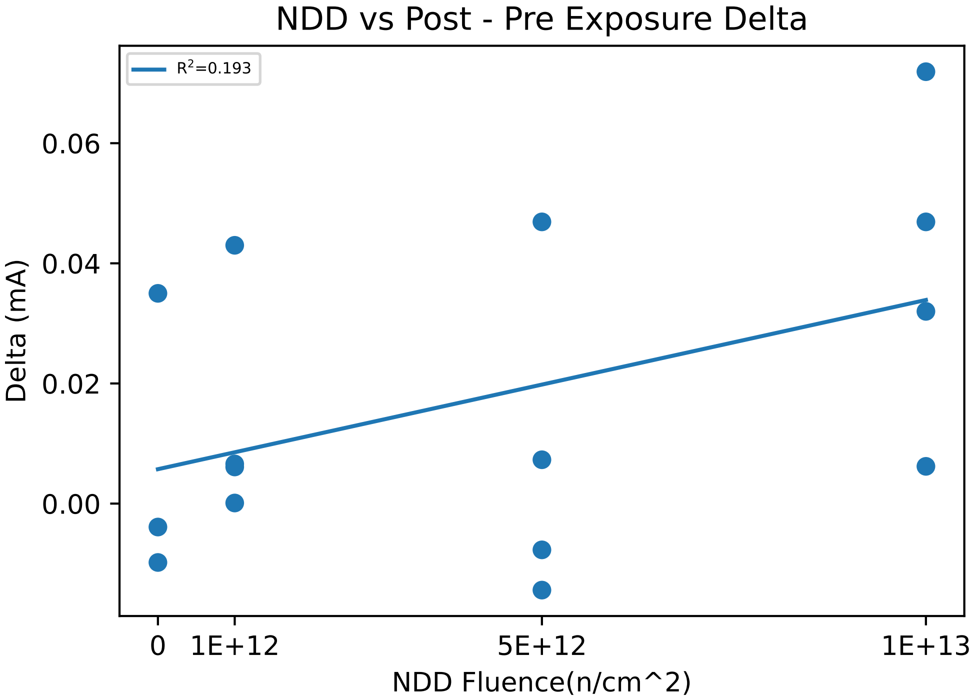
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	11.772	11.771	-0.0013
2	1e+12	NDD	11.642	11.646	0.0049
3	1e+12	NDD	11.96	11.996	0.036
4	1e+12	NDD	11.896	11.9	0.0042
5	5e+12	NDD	11.844	11.828	-0.0157
6	5e+12	NDD	11.912	11.943	0.0305
7	5e+12	NDD	11.803	11.803	-0.0002
8	5e+12	NDD	11.819	11.806	-0.0123
9	1e+13	NDD	11.809	11.861	0.0518
10	1e+13	NDD	11.987	12.005	0.0185
11	1e+13	NDD	11.894	11.89	-0.0037
12	1e+13	NDD	11.934	11.96	0.0259
13	0	CORRELATION	11.781	11.777	-0.0043
14	0	CORRELATION	11.677	11.668	-0.0093
15	0	CORRELATION	11.646	11.674	0.0272

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.646	11.702	11.781	0.0708	11.668	11.706	11.777	0.061561	-0.0093	0.0045333	0.0272	0.019788
1e+12	11.642	11.818	11.96	0.14096	11.646	11.829	11.996	0.15253	-0.0013	0.01095	0.036	0.016929
5e+12	11.803	11.844	11.912	0.048284	11.803	11.845	11.943	0.066181	-0.0157	0.000575	0.0305	0.02103
1e+13	11.809	11.906	11.987	0.075154	11.861	11.929	12.005	0.065813	-0.0037	0.023125	0.0518	0.022883

Device Test: 14.17 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

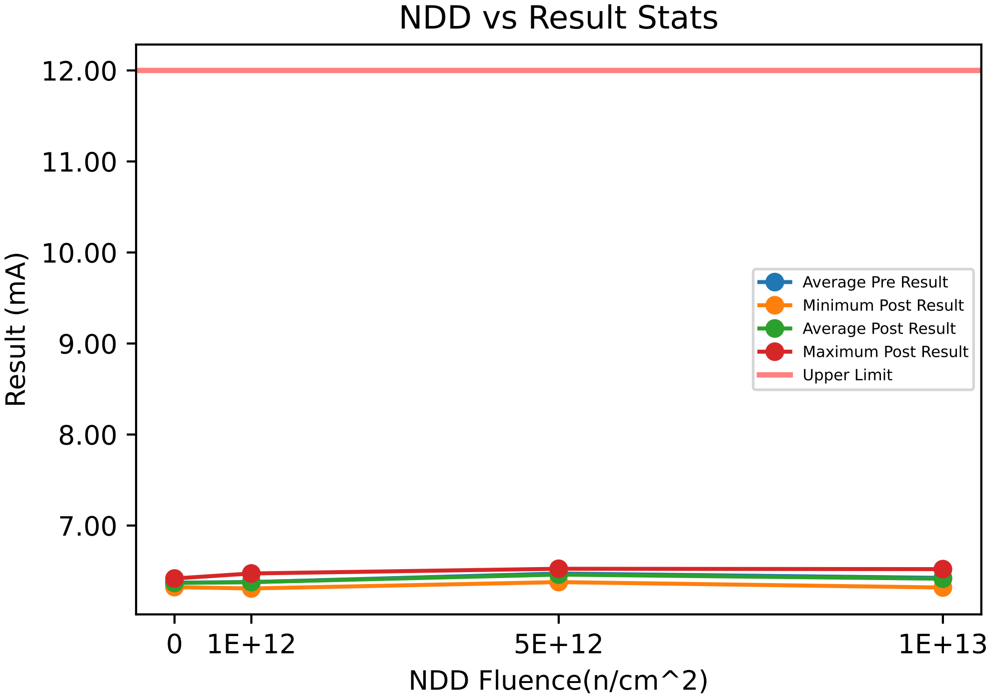
Test Results (Upper Limit = 25.0 (mA))

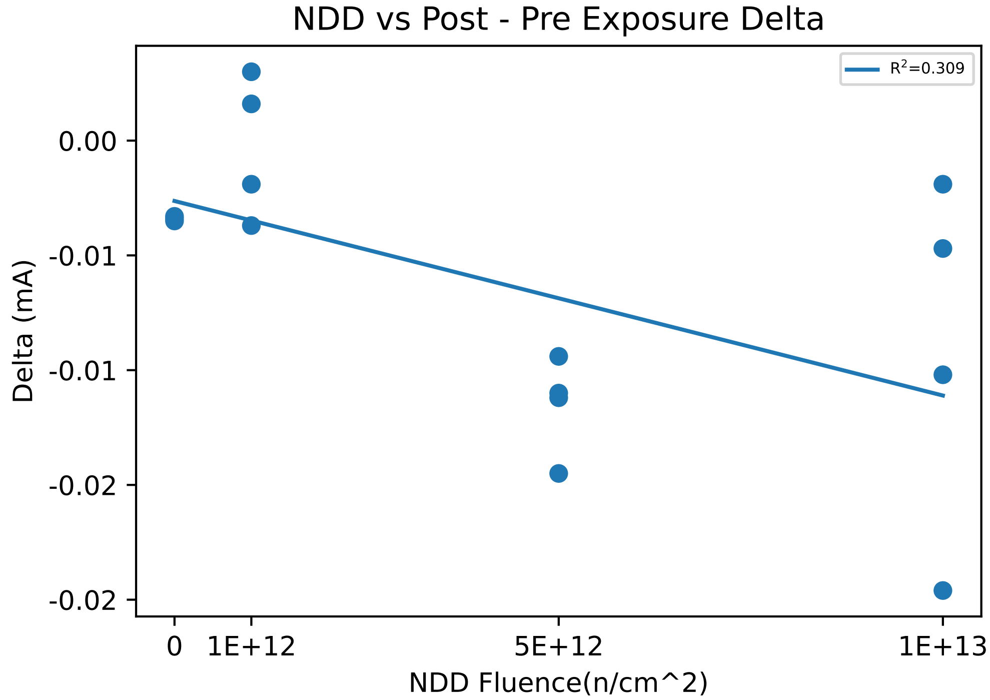
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	12.889	12.889	0.0001
2	1e+12	NDD	12.744	12.751	0.0066
3	1e+12	NDD	13.138	13.181	0.043
4	1e+12	NDD	13.074	13.08	0.0061
5	5e+12	NDD	12.95	12.936	-0.0144
6	5e+12	NDD	13.047	13.094	0.0469
7	5e+12	NDD	12.914	12.922	0.0073
8	5e+12	NDD	12.955	12.947	-0.0077
9	1e+13	NDD	12.976	13.047	0.0719
10	1e+13	NDD	13.215	13.247	0.032
11	1e+13	NDD	13.057	13.063	0.0062
12	1e+13	NDD	13.074	13.121	0.0469
13	0	CORRELATION	12.925	12.921	-0.0039
14	0	CORRELATION	12.777	12.767	-0.0098
15	0	CORRELATION	12.761	12.796	0.035

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.761	12.821	12.925	0.090355	12.767	12.828	12.921	0.081778	-0.0098	0.0071	0.035	0.024342
1e+12	12.744	12.961	13.138	0.17881	12.751	12.975	13.181	0.19213	0.0001	0.01395	0.043	0.019591
5e+12	12.914	12.967	13.047	0.056724	12.922	12.975	13.094	0.080319	-0.0144	0.008025	0.0469	0.027459
1e+13	12.976	13.08	13.215	0.099417	13.047	13.12	13.247	0.090566	0.0062	0.03925	0.0719	0.027504

Device Test: 14.18 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/1000/4.5/100kHz//@IDD_ACT_100K_LOAD_4P5V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

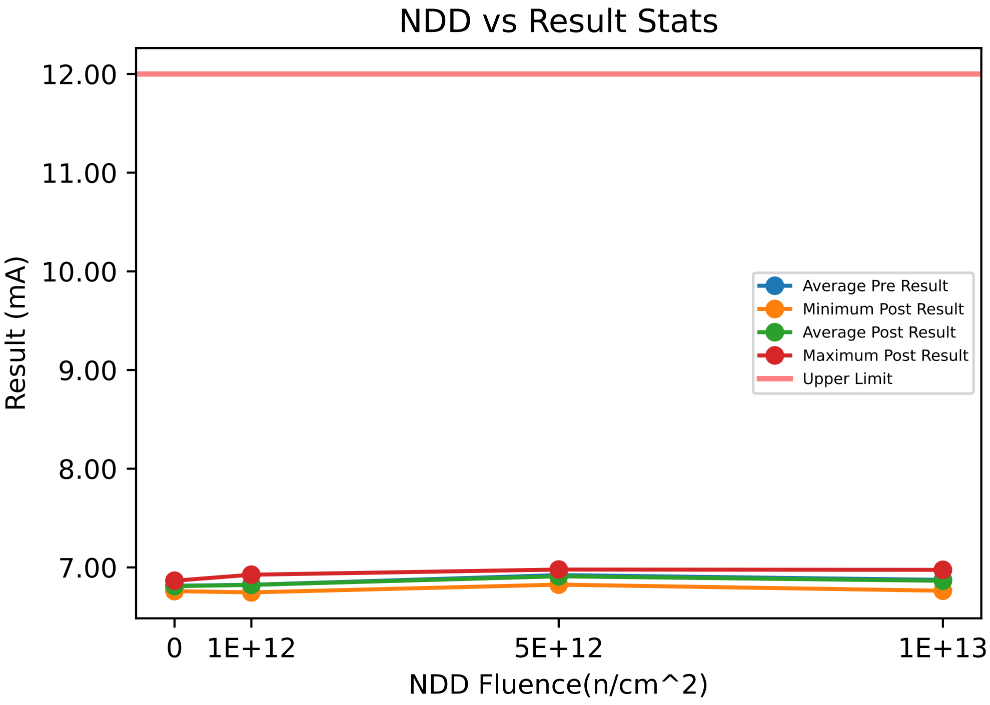
Test Results (Upper Limit = 12.0 (mA))

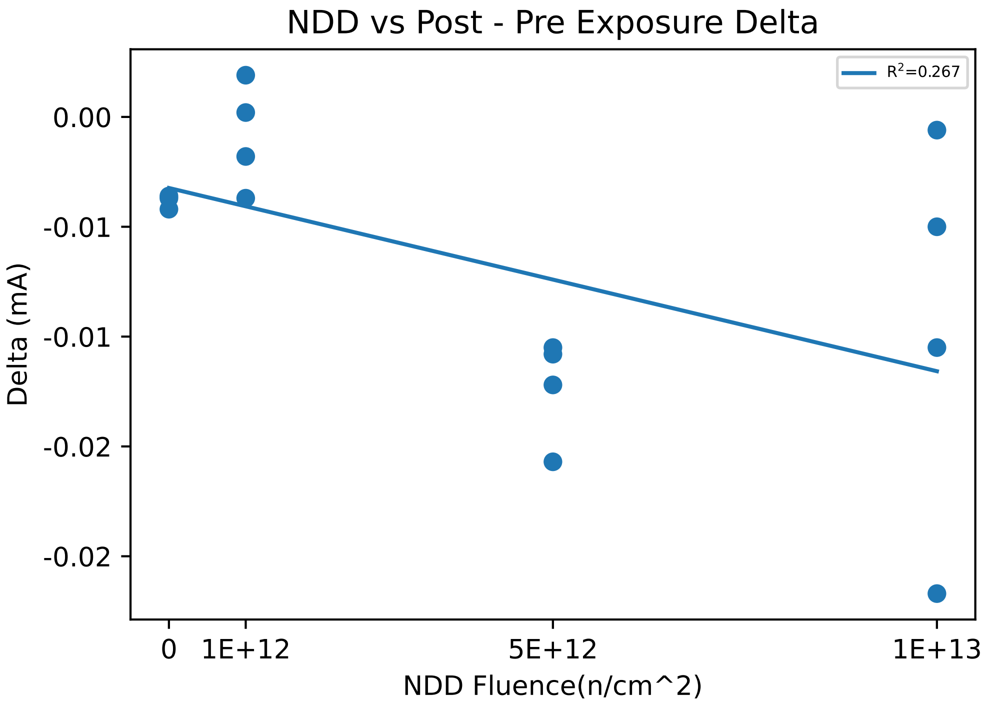
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.3575	6.3538	-0.0037
2	1e+12	NDD	6.3055	6.3085	0.003
3	1e+12	NDD	6.4719	6.4735	0.0016
4	1e+12	NDD	6.3792	6.3773	-0.0019
5	5e+12	NDD	6.536	6.525	-0.011
6	5e+12	NDD	6.4917	6.4772	-0.0145
7	5e+12	NDD	6.4728	6.4634	-0.0094
8	5e+12	NDD	6.3898	6.3786	-0.0112
9	1e+13	NDD	6.3467	6.3448	-0.0019
10	1e+13	NDD	6.3237	6.319	-0.0047
11	1e+13	NDD	6.4885	6.4783	-0.0102
12	1e+13	NDD	6.5406	6.521	-0.0196
13	0	CORRELATION	6.3688	6.3655	-0.0033
14	0	CORRELATION	6.4216	6.4181	-0.0035
15	0	CORRELATION	6.3268	6.3234	-0.0034

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3268	6.3724	6.4216	0.047502	6.3234	6.369	6.4181	0.047447	-0.0035	-0.0034	-0.0033	0.0001
1e+12	6.3055	6.3785	6.4719	0.069508	6.3085	6.3783	6.4735	0.069609	-0.0037	-0.00025	0.003	0.0030881
5e+12	6.3898	6.4726	6.536	0.061211	6.3786	6.4611	6.525	0.060975	-0.0145	-0.011525	-0.0094	0.0021407
1e+13	6.3237	6.4249	6.5406	0.10613	6.319	6.4158	6.521	0.098969	-0.0196	-0.0091	-0.0019	0.007803

Device Test: 14.19 IDD|SUPPLY CURRENT/IN/5/5/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_5V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

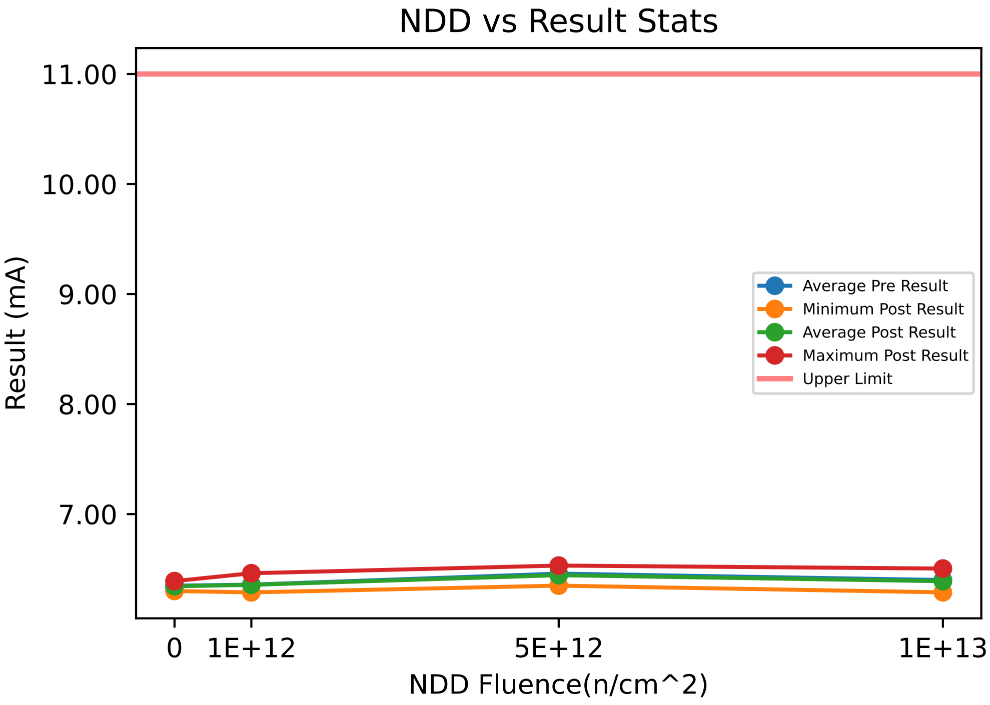
Test Results (Upper Limit = 12.0 (mA))

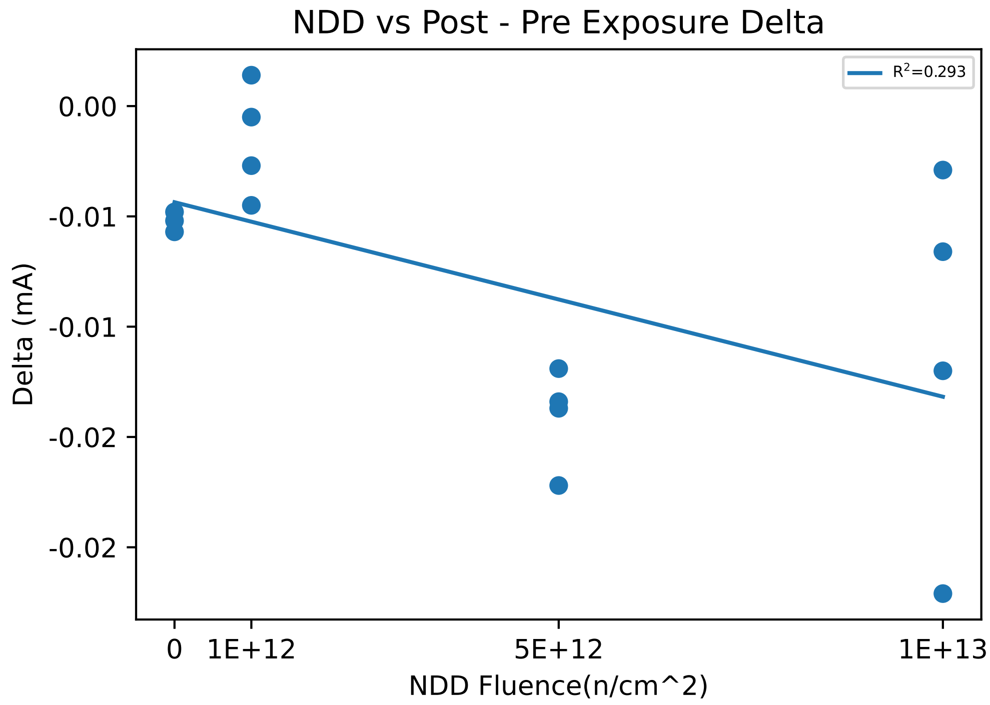
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.8015	6.7978	-0.0037
2	1e+12	NDD	6.7448	6.7467	0.0019
3	1e+12	NDD	6.9258	6.926	0.0002
4	1e+12	NDD	6.8219	6.8201	-0.0018
5	5e+12	NDD	6.9891	6.9783	-0.0108
6	5e+12	NDD	6.9391	6.9234	-0.0157
7	5e+12	NDD	6.9223	6.9118	-0.0105
8	5e+12	NDD	6.8377	6.8255	-0.0122
9	1e+13	NDD	6.7885	6.7879	-0.0006
10	1e+13	NDD	6.7683	6.7633	-0.005
11	1e+13	NDD	6.9409	6.9304	-0.0105
12	1e+13	NDD	6.997	6.9753	-0.0217
13	0	CORRELATION	6.8099	6.8057	-0.0042
14	0	CORRELATION	6.8686	6.865	-0.0036
15	0	CORRELATION	6.7633	6.7596	-0.0037

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7633	6.8139	6.8686	0.052766	6.7596	6.8101	6.865	0.052838	-0.0042	-0.0038333	-0.0036	0.00032146
1e+12	6.7448	6.8235	6.9258	0.075599	6.7467	6.8226	6.926	0.07544	-0.0037	-0.00085	0.0019	0.0024283
5e+12	6.8377	6.922	6.9891	0.062985	6.8255	6.9097	6.9783	0.063213	-0.0157	-0.0123	-0.0105	0.0023847
1e+13	6.7683	6.8737	6.997	0.11267	6.7633	6.8642	6.9753	0.10445	-0.0217	-0.00945	-0.0006	0.0091157

Device Test: 14.2 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

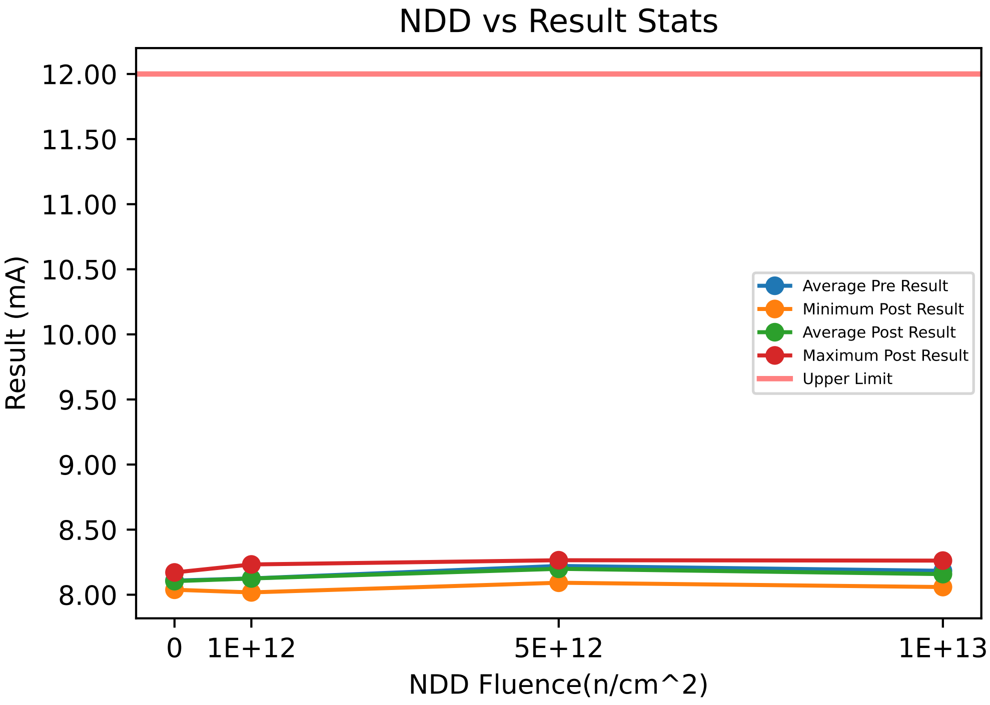
Test Results (Upper Limit = 11.0 (mA))

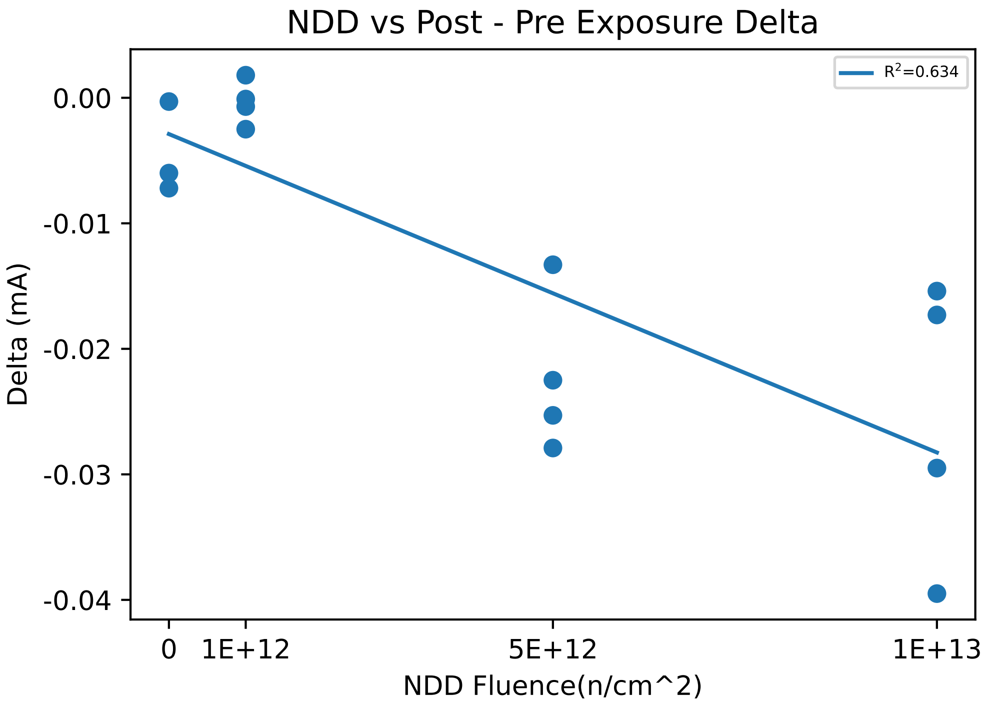
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.3302	6.3257	-0.0045
2	1e+12	NDD	6.2871	6.2885	0.0014
3	1e+12	NDD	6.4632	6.4627	-0.0005
4	1e+12	NDD	6.3547	6.352	-0.0027
5	5e+12	NDD	6.5442	6.5323	-0.0119
6	5e+12	NDD	6.4828	6.4656	-0.0172
7	5e+12	NDD	6.4459	6.4322	-0.0137
8	5e+12	NDD	6.3635	6.3501	-0.0134
9	1e+13	NDD	6.3184	6.3155	-0.0029
10	1e+13	NDD	6.2955	6.2889	-0.0066
11	1e+13	NDD	6.4631	6.4511	-0.012
12	1e+13	NDD	6.5273	6.5052	-0.0221
13	0	CORRELATION	6.3458	6.3401	-0.0057
14	0	CORRELATION	6.3964	6.3912	-0.0052
15	0	CORRELATION	6.3062	6.3014	-0.0048

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3062	6.3495	6.3964	0.045212	6.3014	6.3442	6.3912	0.045042	-0.0057	-0.0052333	-0.0048	0.00045092
1e+12	6.2871	6.3588	6.4632	0.075	6.2885	6.3572	6.4627	0.074987	-0.0045	-0.001575	0.0014	0.0025708
5e+12	6.3635	6.4591	6.5442	0.075537	6.3501	6.4451	6.5323	0.075753	-0.0172	-0.01405	-0.0119	0.0022428
1e+13	6.2955	6.4011	6.5273	0.11219	6.2889	6.3902	6.5052	0.10452	-0.0221	-0.0109	-0.0029	0.0083495

Device Test: 14.20 IDD|SUPPLY CURRENT/IN/12/12/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_12V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

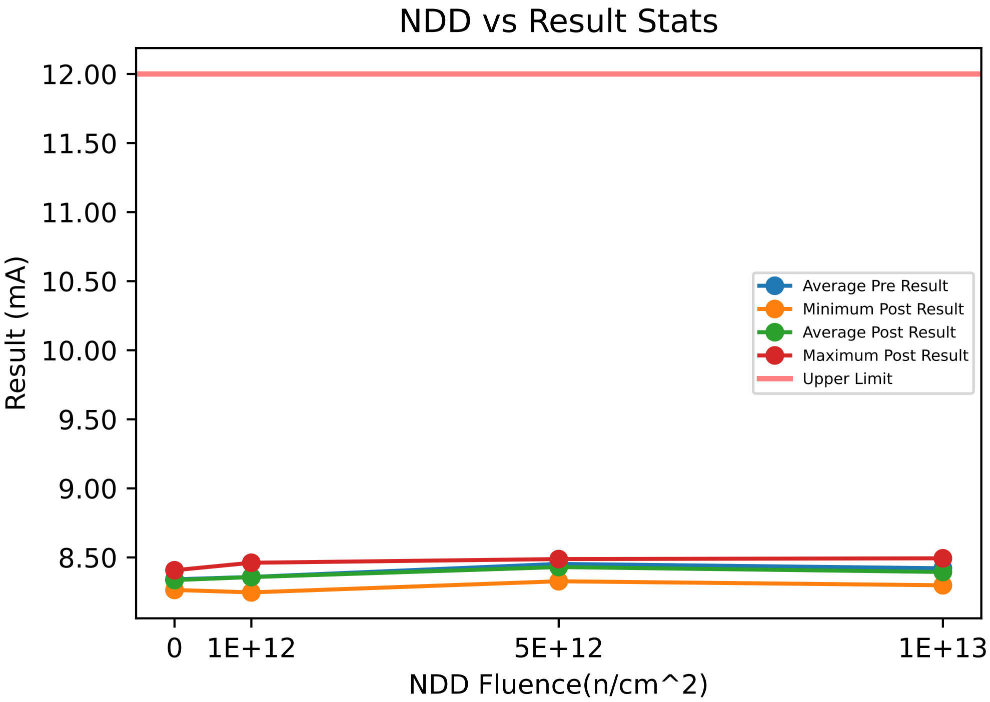
Test Results (Upper Limit = 12.0 (mA))

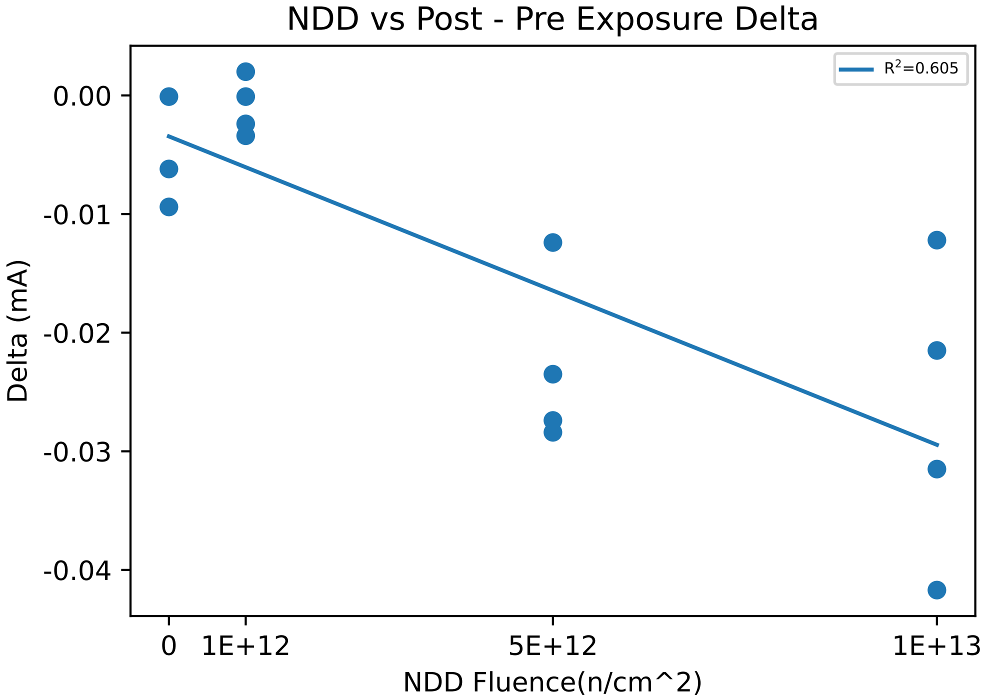
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.1167	8.1142	-0.0025
2	1e+12	NDD	8.0161	8.0179	0.0018
3	1e+12	NDD	8.2333	8.2326	-0.0007
4	1e+12	NDD	8.1351	8.135	-0.0001
5	5e+12	NDD	8.2875	8.265	-0.0225
6	5e+12	NDD	8.2407	8.2154	-0.0253
7	5e+12	NDD	8.2366	8.2233	-0.0133
8	5e+12	NDD	8.12	8.0921	-0.0279
9	1e+13	NDD	8.1119	8.0946	-0.0173
10	1e+13	NDD	8.0744	8.059	-0.0154
11	1e+13	NDD	8.2471	8.2176	-0.0295
12	1e+13	NDD	8.3016	8.2621	-0.0395
13	0	CORRELATION	8.1034	8.1031	-0.0003
14	0	CORRELATION	8.1784	8.1712	-0.0072
15	0	CORRELATION	8.0442	8.0382	-0.006

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0442	8.1087	8.1784	0.067255	8.0382	8.1042	8.1712	0.066506	-0.0072	-0.0045	-0.0003	0.0036865
1e+12	8.0161	8.1253	8.2333	0.088992	8.0179	8.1249	8.2326	0.088062	-0.0025	-0.000375	0.0018	0.0017727
5e+12	8.12	8.2212	8.2875	0.071308	8.0921	8.1989	8.265	0.074483	-0.0279	-0.02225	-0.0133	0.0063611
1e+13	8.0744	8.1837	8.3016	0.10805	8.059	8.1583	8.2621	0.096969	-0.0395	-0.025425	-0.0154	0.011273

Device Test: 14.21 IDD|SUPPLY CURRENT/IN/14/14/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_14V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

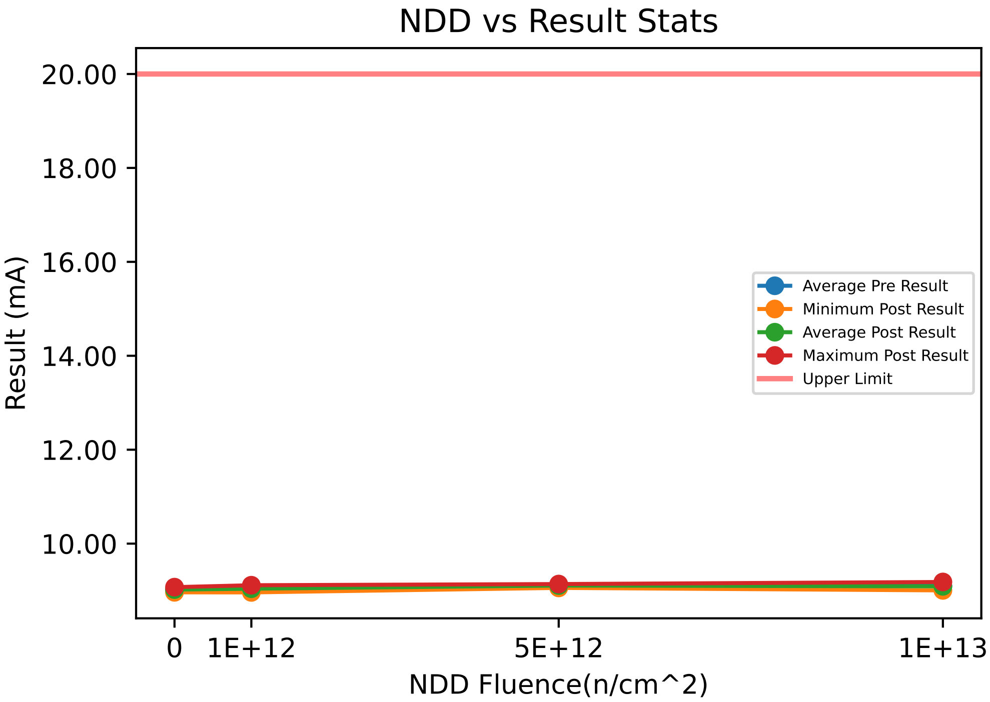
Test Results (Upper Limit = 12.0 (mA))

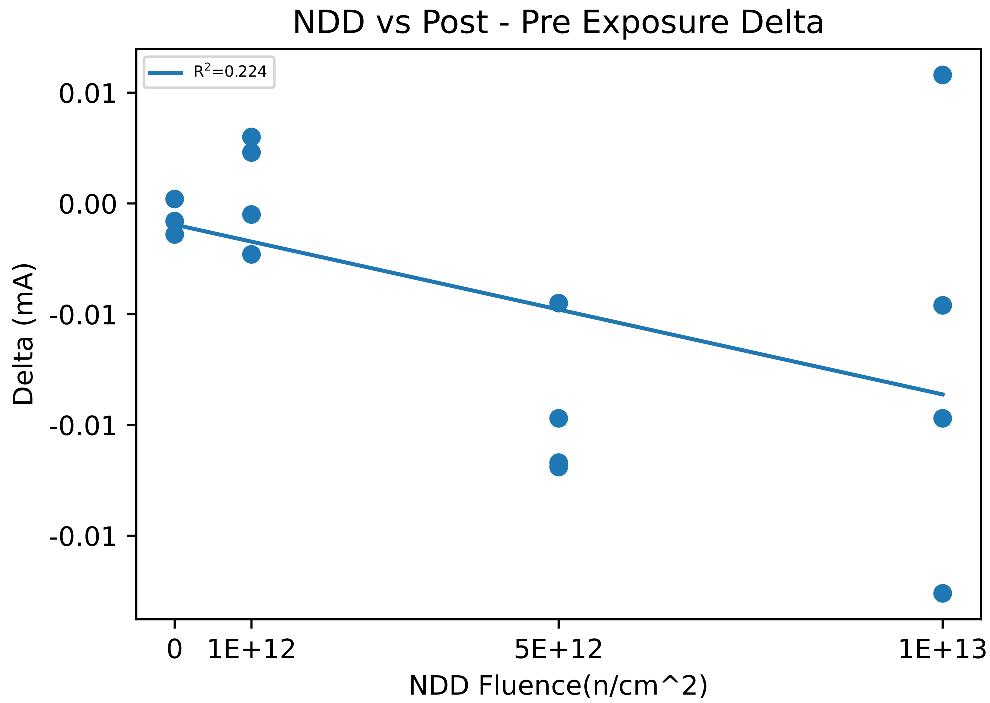
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.3533	8.3509	-0.0024
2	1e+12	NDD	8.2447	8.2467	0.002
3	1e+12	NDD	8.4647	8.4613	-0.0034
4	1e+12	NDD	8.3711	8.371	-0.0001
5	5e+12	NDD	8.5115	8.488	-0.0235
6	5e+12	NDD	8.4718	8.4444	-0.0274
7	5e+12	NDD	8.473	8.4606	-0.0124
8	5e+12	NDD	8.3557	8.3273	-0.0284
9	1e+13	NDD	8.3521	8.3306	-0.0215
10	1e+13	NDD	8.3105	8.2983	-0.0122
11	1e+13	NDD	8.4876	8.4561	-0.0315
12	1e+13	NDD	8.5353	8.4936	-0.0417
13	0	CORRELATION	8.3364	8.3363	-0.0001
14	0	CORRELATION	8.4133	8.4071	-0.0062
15	0	CORRELATION	8.2739	8.2645	-0.0094

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2739	8.3412	8.4133	0.069824	8.2645	8.336	8.4071	0.071301	-0.0094	-0.0052333	-0.0001	0.0047248
1e+12	8.2447	8.3585	8.4647	0.090212	8.2467	8.3575	8.4613	0.088085	-0.0034	-0.000975	0.002	0.0024171
5e+12	8.3557	8.453	8.5115	0.067436	8.3273	8.4301	8.488	0.07084	-0.0284	-0.022925	-0.0124	0.0073282
1e+13	8.3105	8.4214	8.5353	0.10717	8.2983	8.3947	8.4936	0.094786	-0.0417	-0.026725	-0.0122	0.012719

Device Test: 14.22 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/1000/4.5/500kHz//@IDD_ACT_500K_LOAD_4P5V





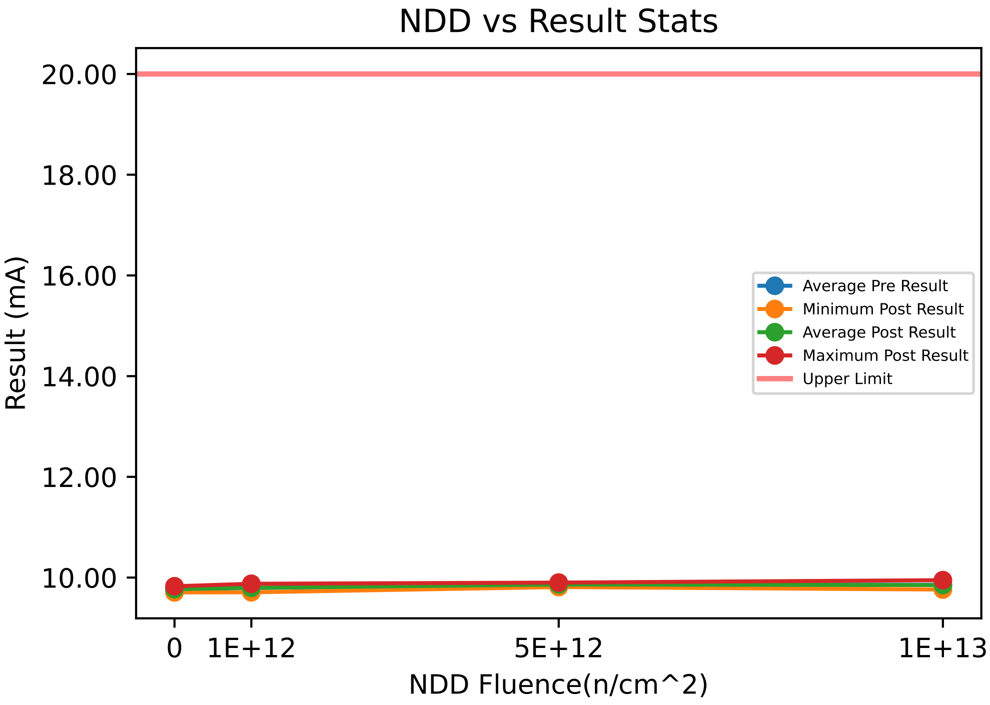
Test Results (Upper Limit = 20.0 (mA))

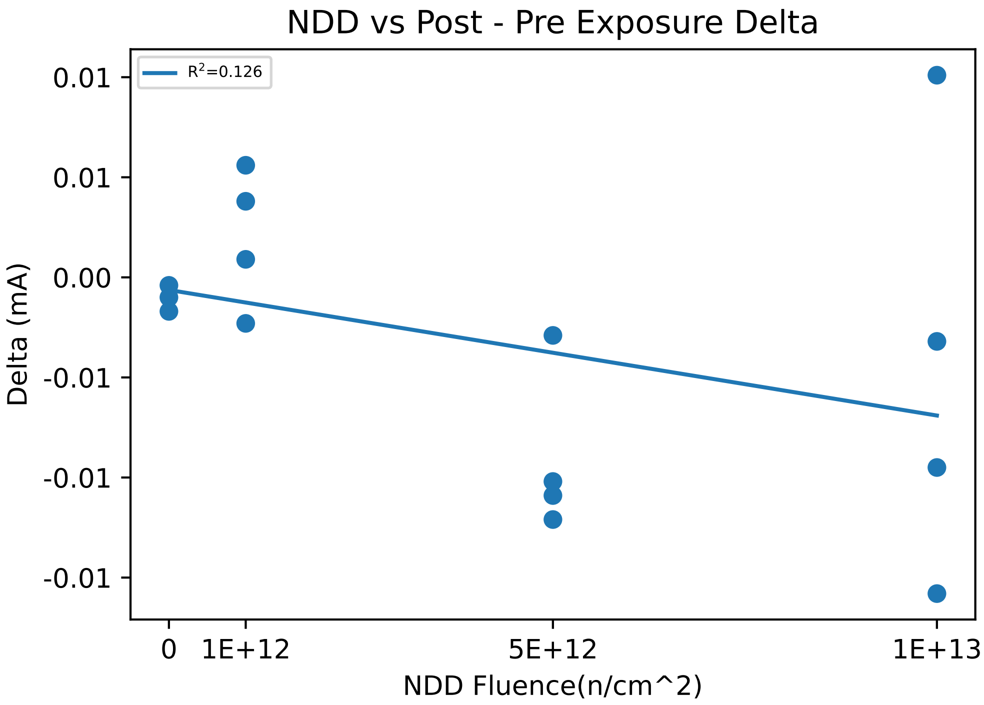
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.0409	9.0386	-0.0023
2	1e+12	NDD	8.9587	8.9617	0.003
3	1e+12	NDD	9.1121	9.1144	0.0023
4	1e+12	NDD	9.0471	9.0466	-0.0005
5	5e+12	NDD	9.1194	9.1097	-0.0097
6	5e+12	NDD	9.1348	9.1229	-0.0119
7	5e+12	NDD	9.1438	9.1393	-0.0045
8	5e+12	NDD	9.0692	9.0575	-0.0117
9	1e+13	NDD	9.0229	9.0287	0.0058
10	1e+13	NDD	9.0091	9.0045	-0.0046
11	1e+13	NDD	9.155	9.1453	-0.0097
12	1e+13	NDD	9.2012	9.1836	-0.0176
13	0	CORRELATION	9.0291	9.0283	-0.0008
14	0	CORRELATION	9.0748	9.0734	-0.0014
15	0	CORRELATION	8.9631	8.9633	0.0002

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.9631	9.0223	9.0748	0.056157	8.9633	9.0217	9.0734	0.055349	-0.0014	-0.00066667	0.0002	0.00080829
1e+12	8.9587	9.0397	9.1121	0.062873	8.9617	9.0403	9.1144	0.06248	-0.0023	0.000625	0.003	0.0024676
5e+12	9.0692	9.1168	9.1438	0.033294	9.0575	9.1074	9.1393	0.03537	-0.0119	-0.00945	-0.0045	0.0034463
1e+13	9.0091	9.097	9.2012	0.095636	9.0045	9.0905	9.1836	0.087342	-0.0176	-0.006525	0.0058	0.0098039

Device Test: 14.23 IDD|SUPPLY CURRENT/IN/5/5/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_5V





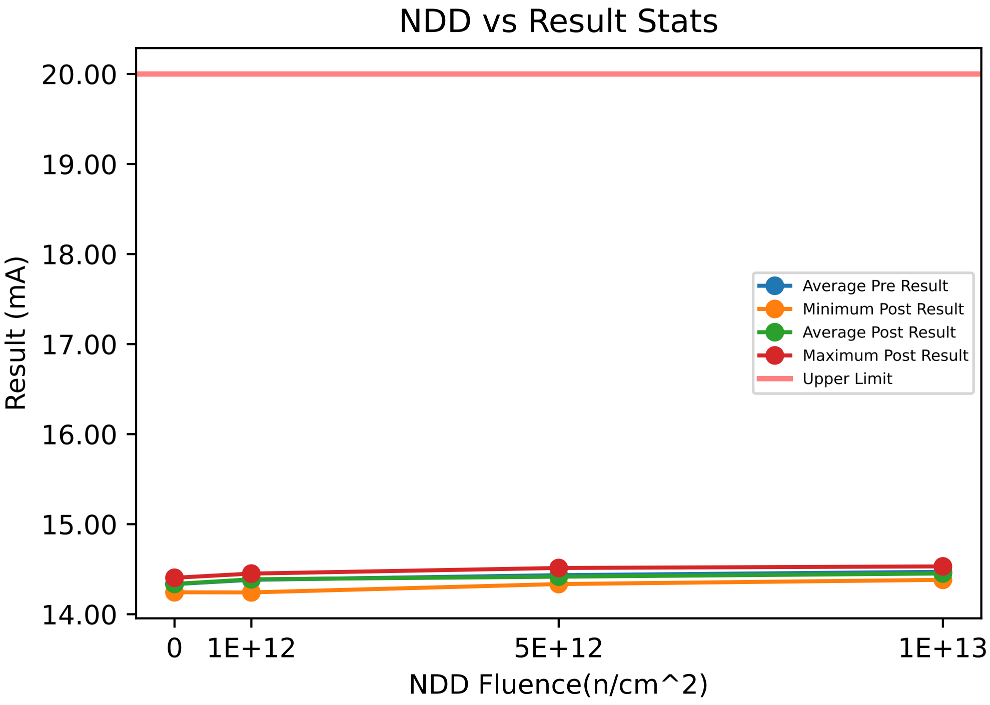
Test Results (Upper Limit = 20.0 (mA))

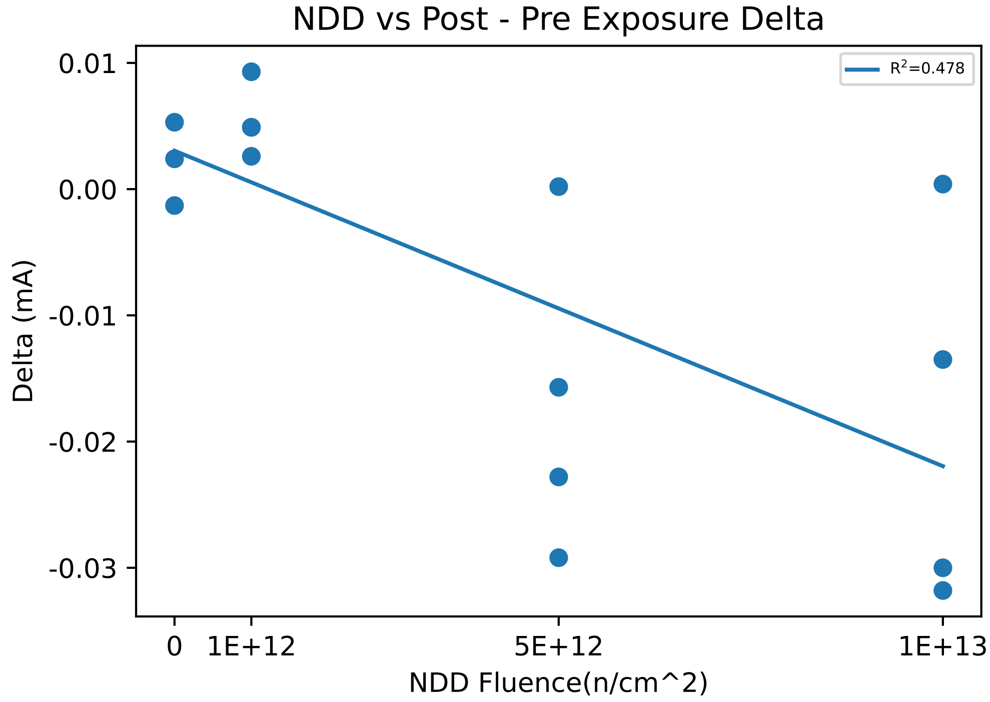
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.7984	9.7961	-0.0023
2	1e+12	NDD	9.7037	9.7075	0.0038
3	1e+12	NDD	9.8712	9.8768	0.0056
4	1e+12	NDD	9.7998	9.8007	0.0009
5	5e+12	NDD	9.871	9.8608	-0.0102
6	5e+12	NDD	9.8874	9.8765	-0.0109
7	5e+12	NDD	9.903	9.9001	-0.0029
8	5e+12	NDD	9.8242	9.8121	-0.0121
9	1e+13	NDD	9.7749	9.785	0.0101
10	1e+13	NDD	9.7654	9.7622	-0.0032
11	1e+13	NDD	9.9173	9.9078	-0.0095
12	1e+13	NDD	9.9643	9.9485	-0.0158
13	0	CORRELATION	9.7773	9.7763	-0.001
14	0	CORRELATION	9.8287	9.827	-0.0017
15	0	CORRELATION	9.7059	9.7055	-0.0004

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7059	9.7706	9.8287	0.061671	9.7055	9.7696	9.827	0.061026	-0.0017	-0.0010333	-0.0004	0.00065064
1e+12	9.7037	9.7933	9.8712	0.068714	9.7075	9.7953	9.8768	0.069236	-0.0023	0.002	0.0056	0.0034593
5e+12	9.8242	9.8714	9.903	0.034071	9.8121	9.8624	9.9001	0.037205	-0.0121	-0.009025	-0.0029	0.004158
1e+13	9.7654	9.8555	9.9643	0.10045	9.7622	9.8509	9.9485	0.091239	-0.0158	-0.0046	0.0101	0.011068

Device Test: 14.24 IDD|SUPPLY CURRENT/IN/12/12/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_12V





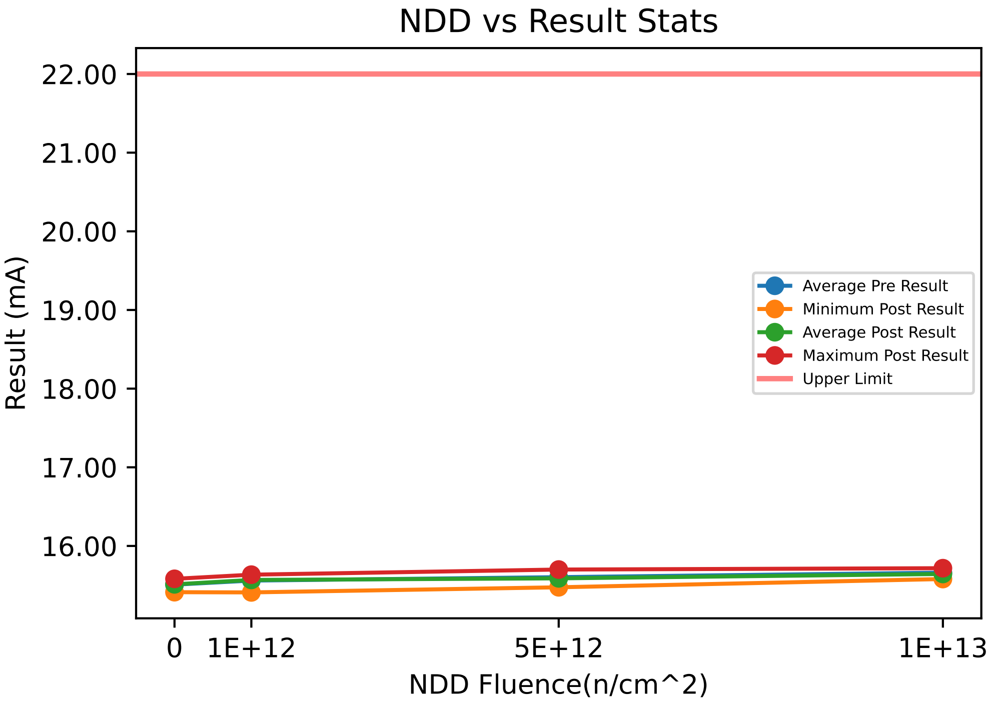
Test Results (Upper Limit = 20.0 (mA))

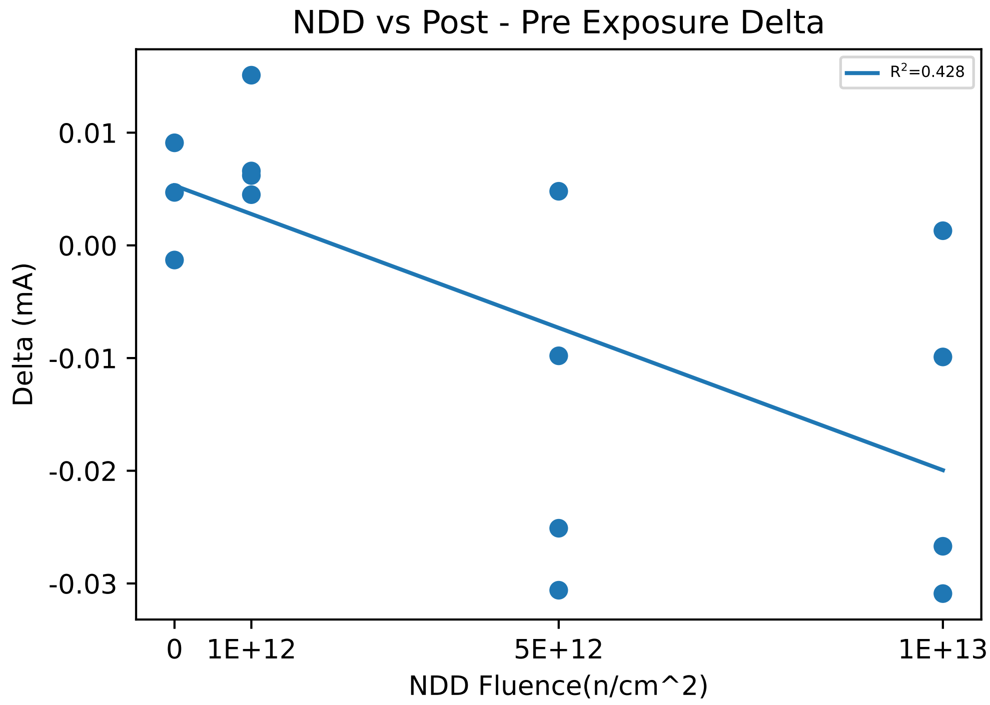
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	14.439	14.442	0.0026
2	1e+12	NDD	14.238	14.242	0.0049
3	1e+12	NDD	14.442	14.451	0.0093
4	1e+12	NDD	14.411	14.415	0.0049
5	5e+12	NDD	14.358	14.335	-0.0228
6	5e+12	NDD	14.453	14.437	-0.0157
7	5e+12	NDD	14.514	14.514	0.0002
8	5e+12	NDD	14.411	14.382	-0.0292
9	1e+13	NDD	14.408	14.409	0.0004
10	1e+13	NDD	14.396	14.382	-0.0135
11	1e+13	NDD	14.518	14.488	-0.03
12	1e+13	NDD	14.563	14.531	-0.0318
13	0	CORRELATION	14.356	14.361	0.0053
14	0	CORRELATION	14.406	14.405	-0.0013
15	0	CORRELATION	14.242	14.244	0.0024

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.242	14.335	14.406	0.084386	14.244	14.337	14.405	0.083245	-0.0013	0.0021333	0.0053	0.0033081
1e+12	14.238	14.382	14.442	0.097569	14.242	14.388	14.451	0.09806	0.0026	0.005425	0.0093	0.0028016
5e+12	14.358	14.434	14.514	0.065768	14.335	14.417	14.514	0.07676	-0.0292	-0.016875	0.0002	0.012648
1e+13	14.396	14.471	14.563	0.082369	14.382	14.453	14.531	0.069237	-0.0318	-0.018725	0.0004	0.015178

Device Test: 14.25 IDD|SUPPLY CURRENT/IN/14/14/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_14V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

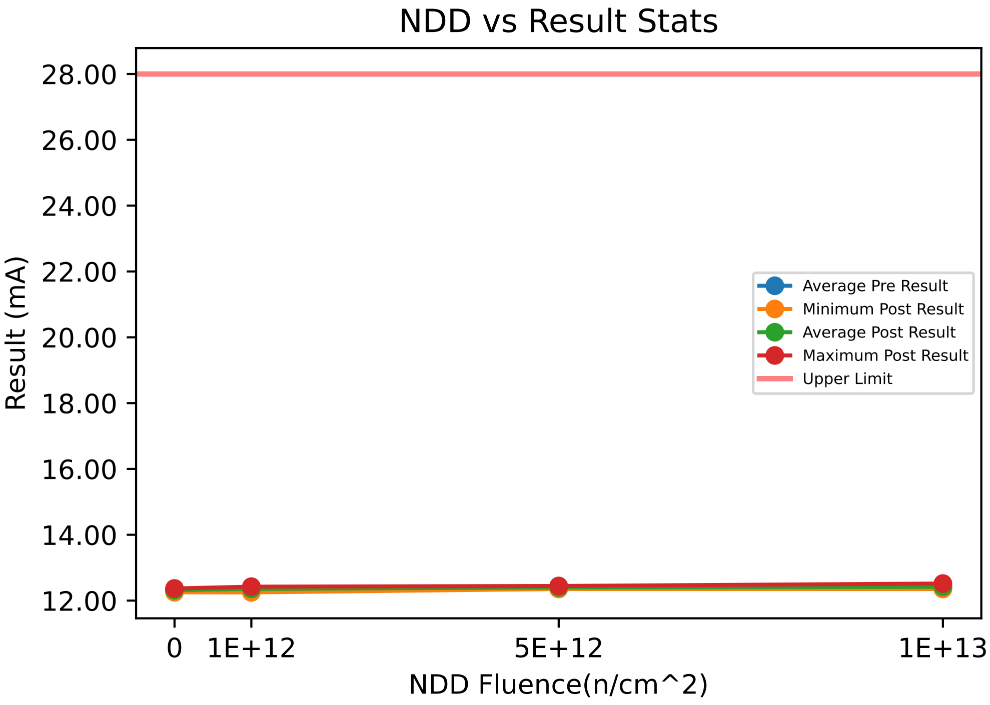
Test Results (Upper Limit = 22.0 (mA))

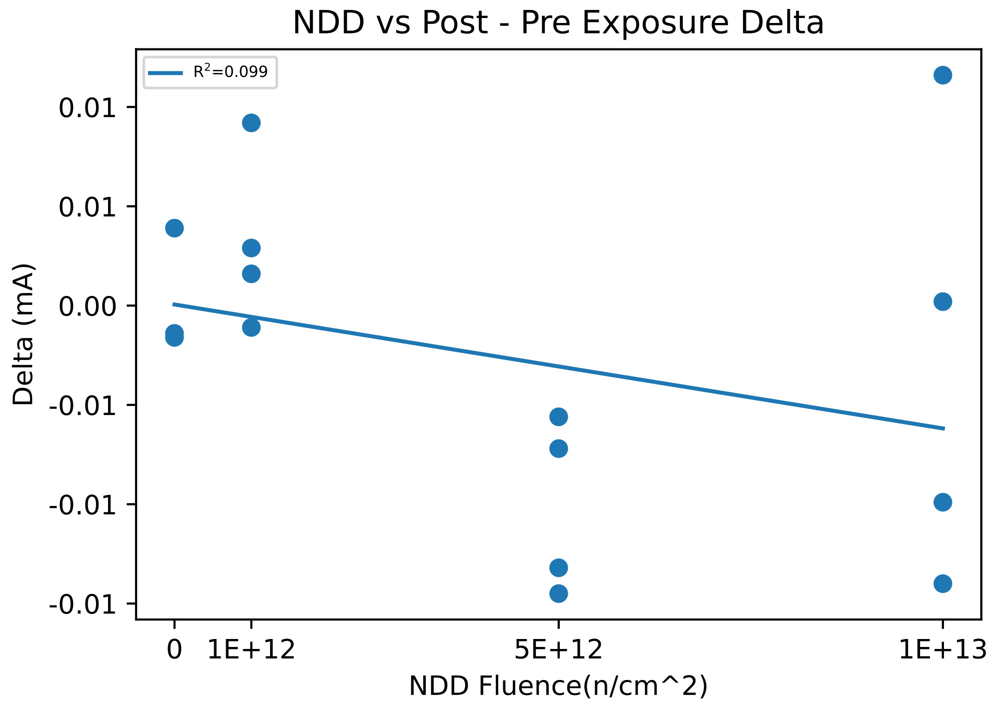
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	15.63	15.635	0.0045
2	1e+12	NDD	15.403	15.409	0.0062
3	1e+12	NDD	15.611	15.626	0.0151
4	1e+12	NDD	15.595	15.602	0.0066
5	5e+12	NDD	15.499	15.474	-0.0251
6	5e+12	NDD	15.622	15.612	-0.0098
7	5e+12	NDD	15.695	15.7	0.0048
8	5e+12	NDD	15.597	15.566	-0.0306
9	1e+13	NDD	15.604	15.605	0.0013
10	1e+13	NDD	15.589	15.579	-0.0099
11	1e+13	NDD	15.705	15.674	-0.0309
12	1e+13	NDD	15.744	15.717	-0.0267
13	0	CORRELATION	15.533	15.542	0.0091
14	0	CORRELATION	15.583	15.582	-0.0013
15	0	CORRELATION	15.408	15.412	0.0047

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.408	15.508	15.583	0.09043	15.412	15.512	15.582	0.088663	-0.0013	0.0041667	0.0091	0.0052205
1e+12	15.403	15.56	15.63	0.10539	15.409	15.568	15.635	0.1066	0.0045	0.0081	0.0151	0.0047546
5e+12	15.499	15.603	15.695	0.0809	15.474	15.588	15.7	0.094066	-0.0306	-0.015175	0.0048	0.015962
1e+13	15.589	15.66	15.744	0.075774	15.579	15.644	15.717	0.063125	-0.0309	-0.01655	0.0013	0.014964

Device Test: 14.26 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/1000/4.5/1MHz//@IDD_ACT_1M_LOAD_4P5V





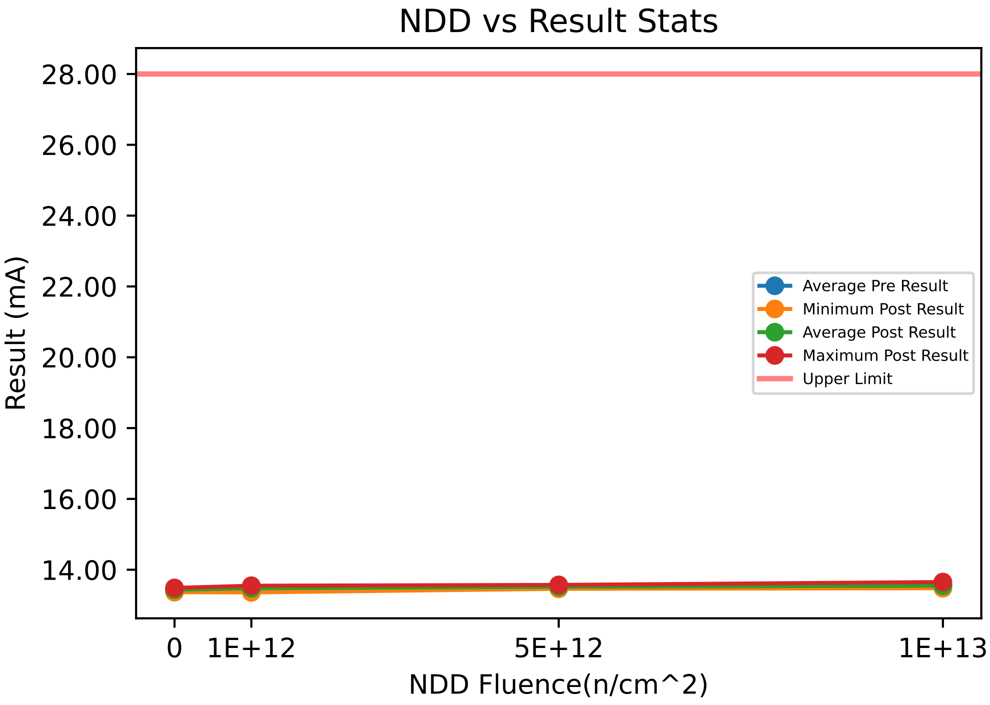
Test Results (Upper Limit = 28.0 (mA))

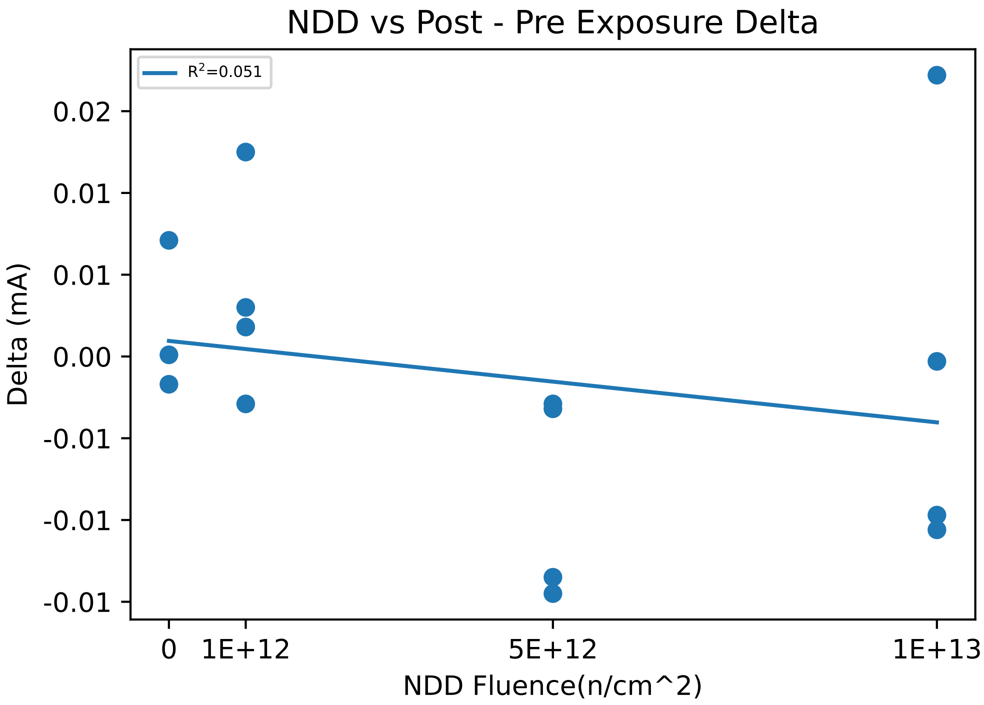
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	12.385	12.384	-0.0011
2	1e+12	NDD	12.246	12.249	0.0029
3	1e+12	NDD	12.414	12.423	0.0092
4	1e+12	NDD	12.362	12.364	0.0016
5	5e+12	NDD	12.366	12.353	-0.0132
6	5e+12	NDD	12.436	12.428	-0.0072
7	5e+12	NDD	12.45	12.445	-0.0056
8	5e+12	NDD	12.386	12.371	-0.0145
9	1e+13	NDD	12.347	12.358	0.0116
10	1e+13	NDD	12.351	12.352	0.0002
11	1e+13	NDD	12.466	12.456	-0.0099
12	1e+13	NDD	12.533	12.518	-0.014
13	0	CORRELATION	12.338	12.337	-0.0014
14	0	CORRELATION	12.371	12.369	-0.0016
15	0	CORRELATION	12.25	12.254	0.0039

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.25	12.32	12.371	0.062333	12.254	12.32	12.369	0.059299	-0.0016	0.0003	0.0039	0.0031193
1e+12	12.246	12.352	12.414	0.073423	12.249	12.355	12.423	0.074668	-0.0011	0.00315	0.0092	0.0043639
5e+12	12.366	12.41	12.45	0.039837	12.353	12.399	12.445	0.044014	-0.0145	-0.010125	-0.0056	0.0043828
1e+13	12.347	12.424	12.533	0.090932	12.352	12.421	12.518	0.080634	-0.014	-0.003025	0.0116	0.011431

Device Test: 14.27 IDD|SUPPLY CURRENT/IN/5/5/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_5V





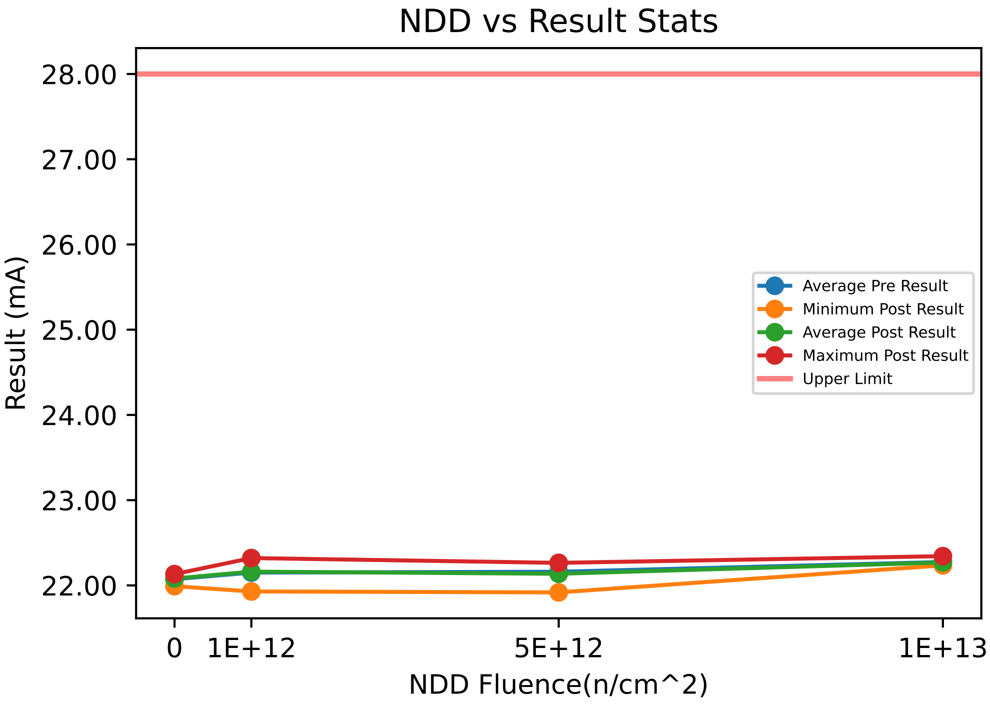
Test Results (Upper Limit = 28.0 (mA))

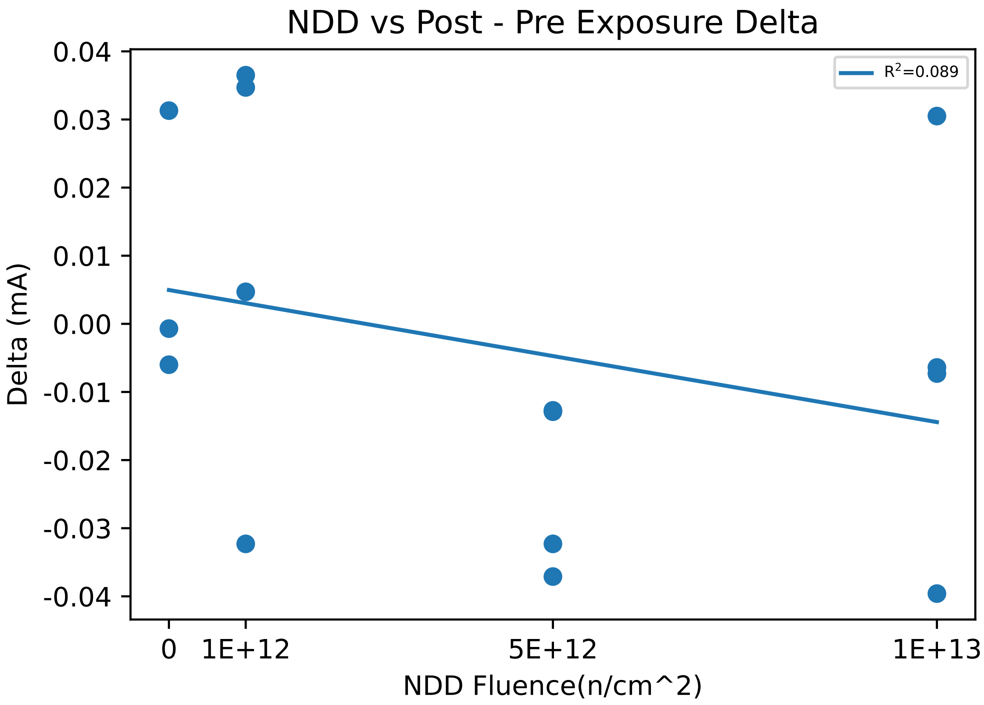
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	13.513	13.51	-0.0029
2	1e+12	NDD	13.357	13.36	0.003
3	1e+12	NDD	13.536	13.548	0.0125
4	1e+12	NDD	13.482	13.484	0.0018
5	5e+12	NDD	13.475	13.461	-0.0135
6	5e+12	NDD	13.553	13.55	-0.0032
7	5e+12	NDD	13.574	13.571	-0.0029
8	5e+12	NDD	13.512	13.498	-0.0145
9	1e+13	NDD	13.469	13.486	0.0172
10	1e+13	NDD	13.478	13.478	-0.0003
11	1e+13	NDD	13.593	13.582	-0.0106
12	1e+13	NDD	13.662	13.652	-0.0097
13	0	CORRELATION	13.453	13.454	0.0001
14	0	CORRELATION	13.488	13.486	-0.0017
15	0	CORRELATION	13.359	13.366	0.0071

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.359	13.433	13.488	0.066963	13.366	13.435	13.486	0.062326	-0.0017	0.0018333	0.0071	0.004649
1e+12	13.357	13.472	13.536	0.079795	13.36	13.475	13.548	0.081517	-0.0029	0.0036	0.0125	0.0064565
5e+12	13.475	13.529	13.574	0.044211	13.461	13.52	13.571	0.04997	-0.0145	-0.008525	-0.0029	0.0063363
1e+13	13.469	13.55	13.662	0.093328	13.478	13.55	13.652	0.083275	-0.0106	-0.00085	0.0172	0.012903

Device Test: 14.28 IDD|SUPPLY CURRENT/IN/12/12/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_12V





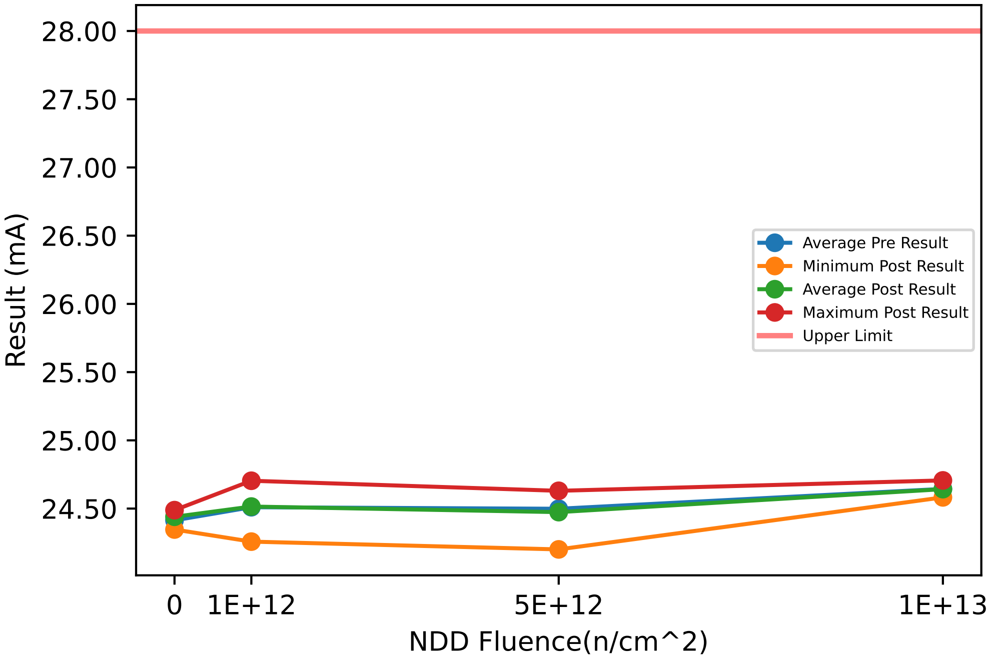
Test Results (Upper Limit = 28.0 (mA))

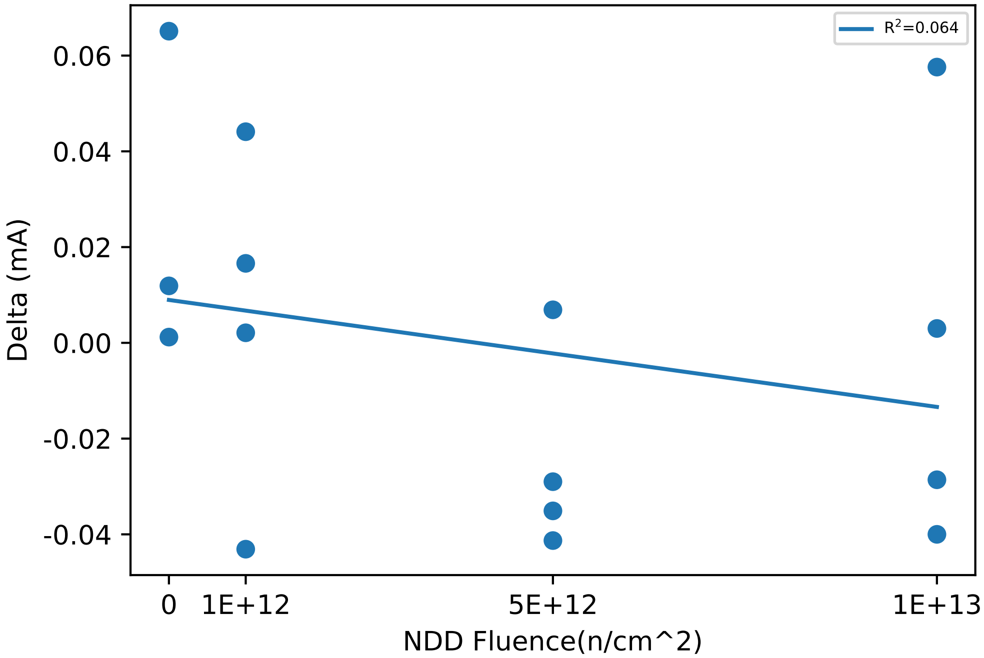
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	22.286	22.321	0.0347
2	1e+12	NDD	21.924	21.929	0.0047
3	1e+12	NDD	22.166	22.203	0.0365
4	1e+12	NDD	22.224	22.192	-0.0323
5	5e+12	NDD	21.95	21.918	-0.0323
6	5e+12	NDD	22.2	22.187	-0.0127
7	5e+12	NDD	22.277	22.264	-0.0129
8	5e+12	NDD	22.214	22.177	-0.0371
9	1e+13	NDD	22.216	22.247	0.0305
10	1e+13	NDD	22.257	22.251	-0.0064
11	1e+13	NDD	22.274	22.235	-0.0396
12	1e+13	NDD	22.35	22.343	-0.0073
13	0	CORRELATION	22.125	22.119	-0.006
14	0	CORRELATION	22.133	22.132	-0.0007
15	0	CORRELATION	21.959	21.991	0.0313

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.959	22.073	22.133	0.098077	21.991	22.081	22.132	0.078262	-0.006	0.0082	0.0313	0.02018
1e+12	21.924	22.15	22.286	0.15846	21.929	22.161	22.321	0.16546	-0.0323	0.0109	0.0365	0.032283
5e+12	21.95	22.16	22.277	0.14411	21.918	22.137	22.264	0.15097	-0.0371	-0.02375	-0.0127	0.012795
1e+13	22.216	22.274	22.35	0.056017	22.235	22.269	22.343	0.049814	-0.0396	-0.0057	0.0305	0.028651

Device Test: 14.29 IDD|SUPPLY CURRENT/IN/14/14/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_14V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

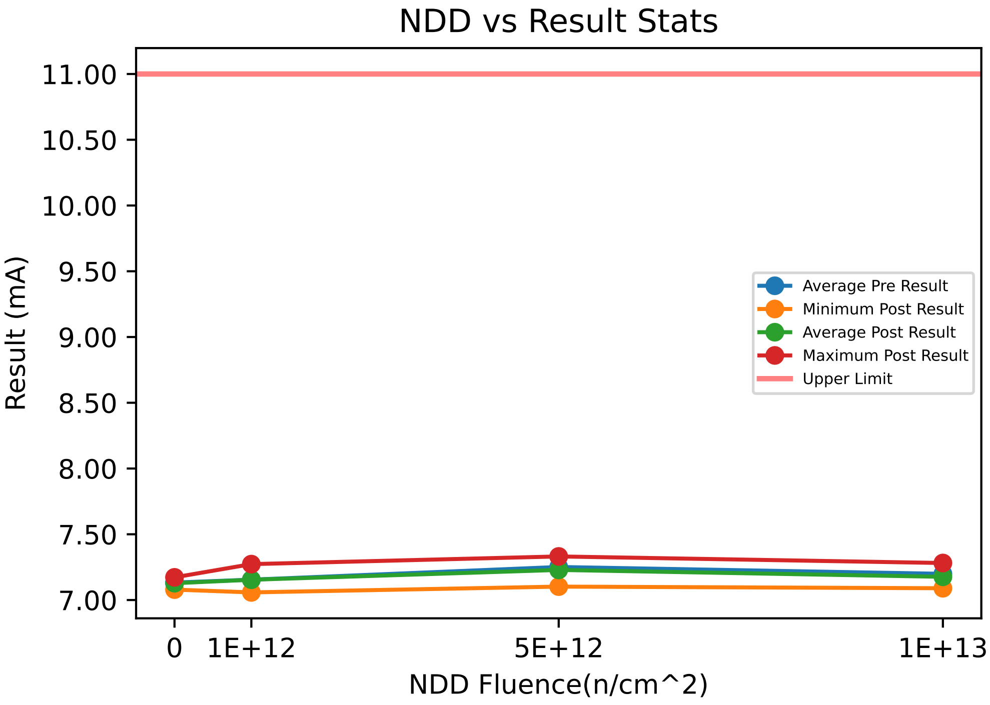
Test Results (Upper Limit = 28.0 (mA))

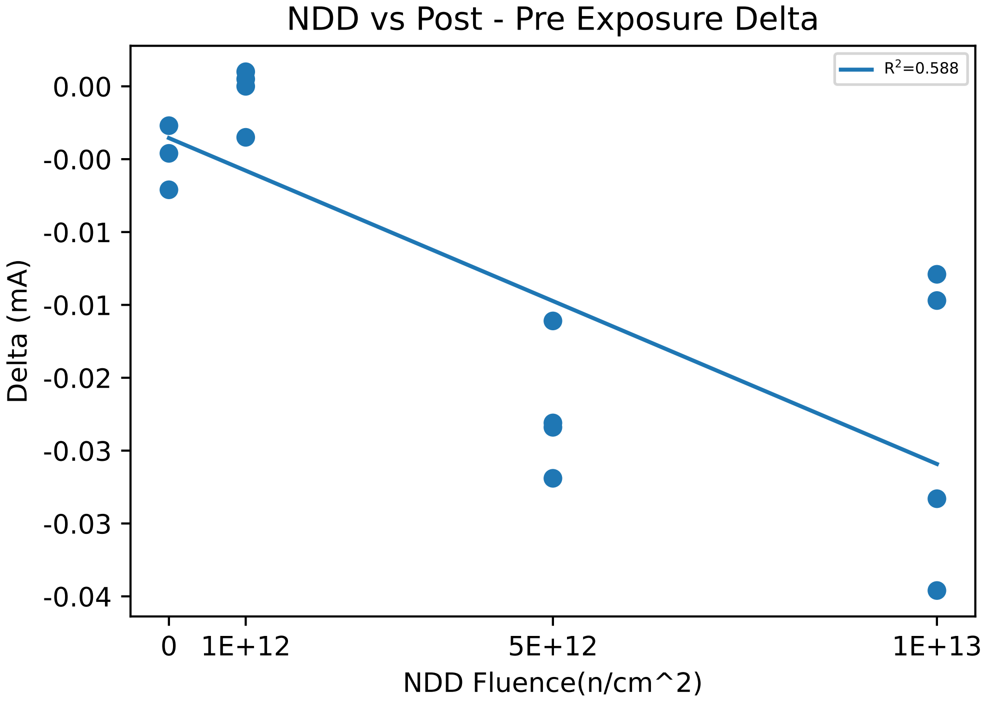
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	24.687	24.704	0.0166
2	1e+12	NDD	24.256	24.258	0.0021
3	1e+12	NDD	24.5	24.544	0.0441
4	1e+12	NDD	24.597	24.554	-0.0431
5	5e+12	NDD	24.236	24.201	-0.0351
6	5e+12	NDD	24.561	24.532	-0.029
7	5e+12	NDD	24.623	24.63	0.0069
8	5e+12	NDD	24.574	24.533	-0.0413
9	1e+13	NDD	24.585	24.643	0.0576
10	1e+13	NDD	24.666	24.638	-0.0286
11	1e+13	NDD	24.622	24.582	-0.04
12	1e+13	NDD	24.703	24.706	0.003
13	0	CORRELATION	24.473	24.485	0.0119
14	0	CORRELATION	24.487	24.488	0.0012
15	0	CORRELATION	24.281	24.346	0.0651

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.281	24.414	24.487	0.11487	24.346	24.44	24.488	0.080854	0.0012	0.026067	0.0651	0.034225
1e+12	24.256	24.51	24.687	0.18601	24.258	24.515	24.704	0.18635	-0.0431	0.004925	0.0441	0.036448
5e+12	24.236	24.499	24.623	0.17719	24.201	24.474	24.63	0.18788	-0.0413	-0.024625	0.0069	0.021608
1e+13	24.585	24.644	24.703	0.051557	24.582	24.642	24.706	0.05084	-0.04	-0.002	0.0576	0.043699

Device Test: 14.3 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





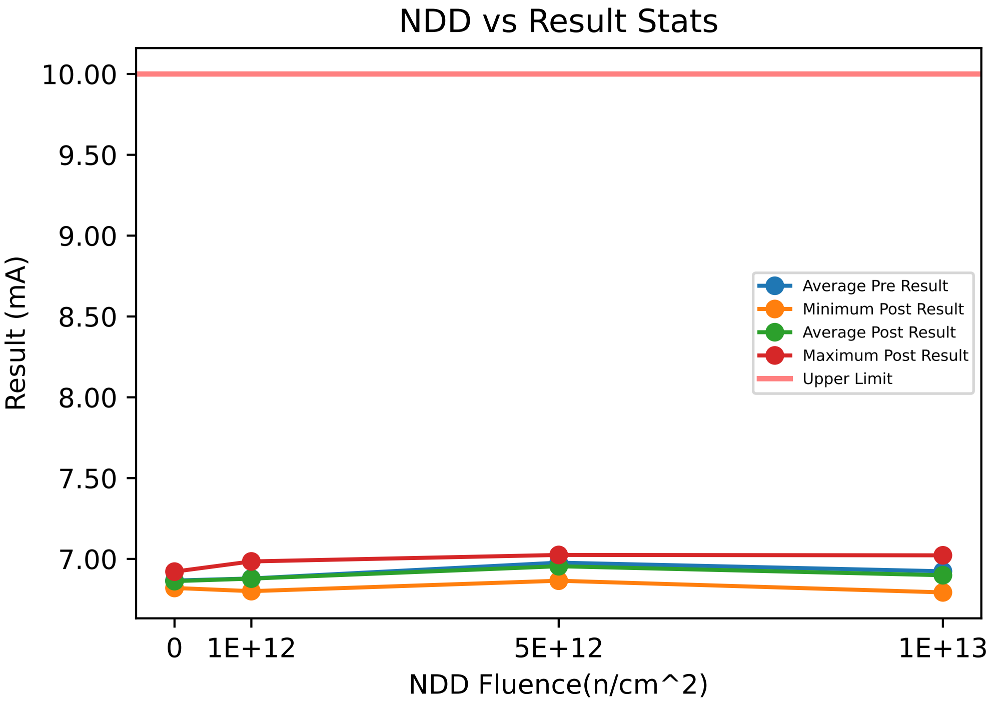
Test Results (Upper Limit = 11.0 (mA))

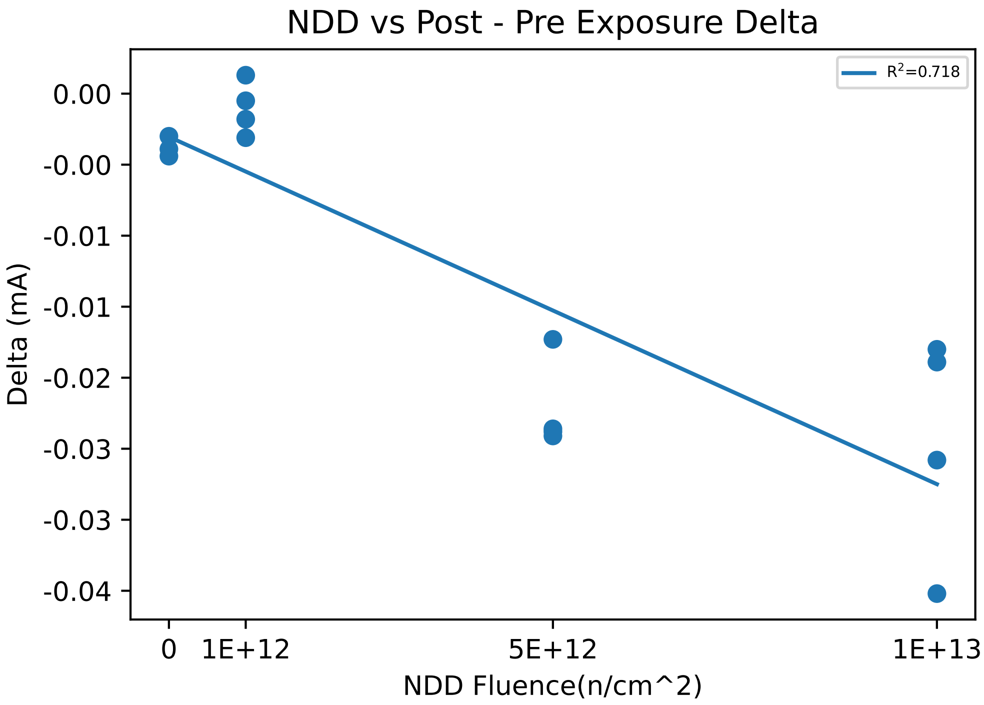
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1259	7.1224	-0.0035
2	1e+12	NDD	7.057	7.058	0.001
3	1e+12	NDD	7.273	7.273	0
4	1e+12	NDD	7.163	7.1635	0.0005
5	5e+12	NDD	7.3548	7.3314	-0.0234
6	5e+12	NDD	7.2853	7.2622	-0.0231
7	5e+12	NDD	7.2359	7.2198	-0.0161
8	5e+12	NDD	7.1289	7.102	-0.0269
9	1e+13	NDD	7.129	7.1143	-0.0147
10	1e+13	NDD	7.1025	7.0896	-0.0129
11	1e+13	NDD	7.2494	7.2211	-0.0283
12	1e+13	NDD	7.3161	7.2815	-0.0346
13	0	CORRELATION	7.1347	7.132	-0.0027
14	0	CORRELATION	7.1795	7.1724	-0.0071
15	0	CORRELATION	7.0839	7.0793	-0.0046

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0839	7.1327	7.1795	0.047831	7.0793	7.1279	7.1724	0.046685	-0.0071	-0.0048	-0.0027	0.0022068
1e+12	7.057	7.1547	7.273	0.090256	7.058	7.1542	7.273	0.090306	-0.0035	-0.0005	0.001	0.0020412
5e+12	7.1289	7.2512	7.3548	0.095021	7.102	7.2289	7.3314	0.096266	-0.0269	-0.022375	-0.0161	0.004525
1e+13	7.1025	7.1992	7.3161	0.10077	7.0896	7.1766	7.2815	0.090249	-0.0346	-0.022625	-0.0129	0.010535

Device Test: 14.30 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_LDO





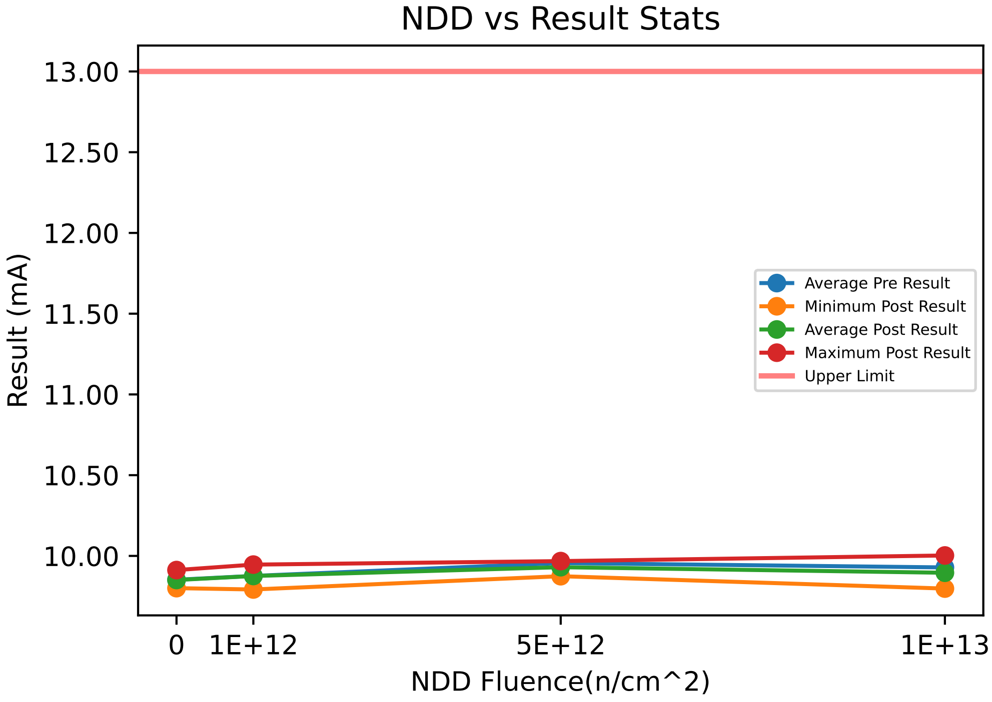
Test Results (Upper Limit = 10.0 (mA))

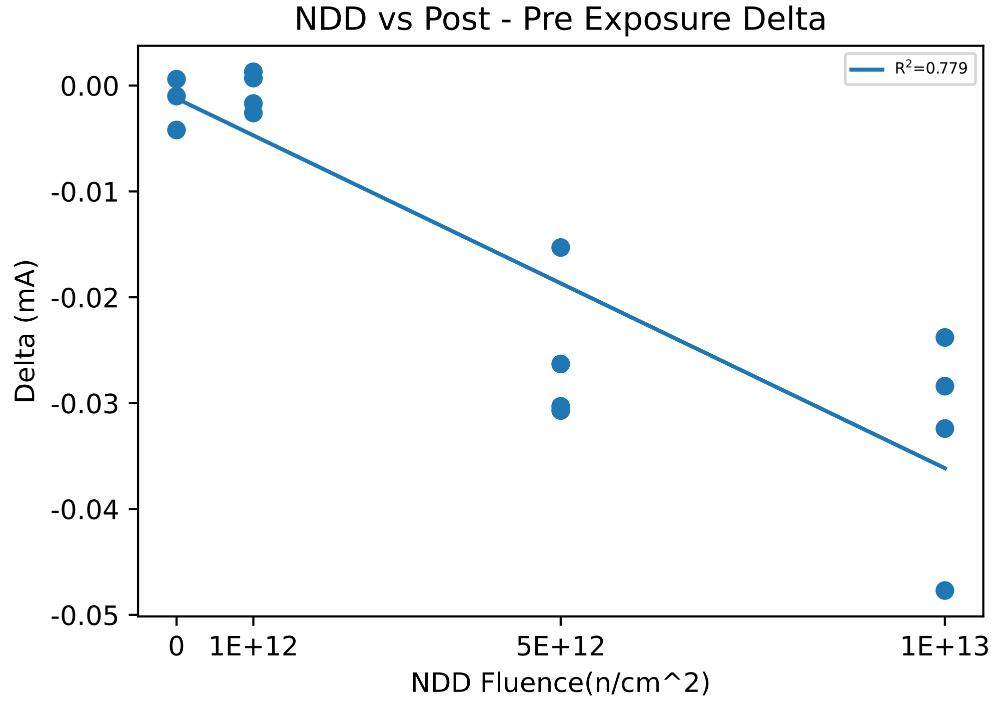
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.8552	6.8521	-0.0031
2	1e+12	NDD	6.7994	6.8007	0.0013
3	1e+12	NDD	6.9851	6.9846	-0.0005
4	1e+12	NDD	6.8771	6.8753	-0.0018
5	5e+12	NDD	7.0483	7.0247	-0.0236
6	5e+12	NDD	6.9981	6.974	-0.0241
7	5e+12	NDD	6.9727	6.9554	-0.0173
8	5e+12	NDD	6.889	6.8652	-0.0238
9	1e+13	NDD	6.8281	6.8101	-0.018
10	1e+13	NDD	6.8119	6.793	-0.0189
11	1e+13	NDD	6.9971	6.9713	-0.0258
12	1e+13	NDD	7.0576	7.0224	-0.0352
13	0	CORRELATION	6.8491	6.8461	-0.003
14	0	CORRELATION	6.9259	6.9215	-0.0044
15	0	CORRELATION	6.8243	6.8204	-0.0039

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.8243	6.8664	6.9259	0.052971	6.8204	6.8627	6.9215	0.052547	-0.0044	-0.0037667	-0.003	0.00070946
1e+12	6.7994	6.8792	6.9851	0.07781	6.8007	6.8782	6.9846	0.077496	-0.0031	-0.001025	0.0013	0.0018786
5e+12	6.889	6.977	7.0483	0.066562	6.8652	6.9548	7.0247	0.066541	-0.0241	-0.0222	-0.0173	0.0032731
1e+13	6.8119	6.9237	7.0576	0.12241	6.793	6.8992	7.0224	0.11488	-0.0352	-0.024475	-0.018	0.0079538

Device Test: 14.31 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_LDO





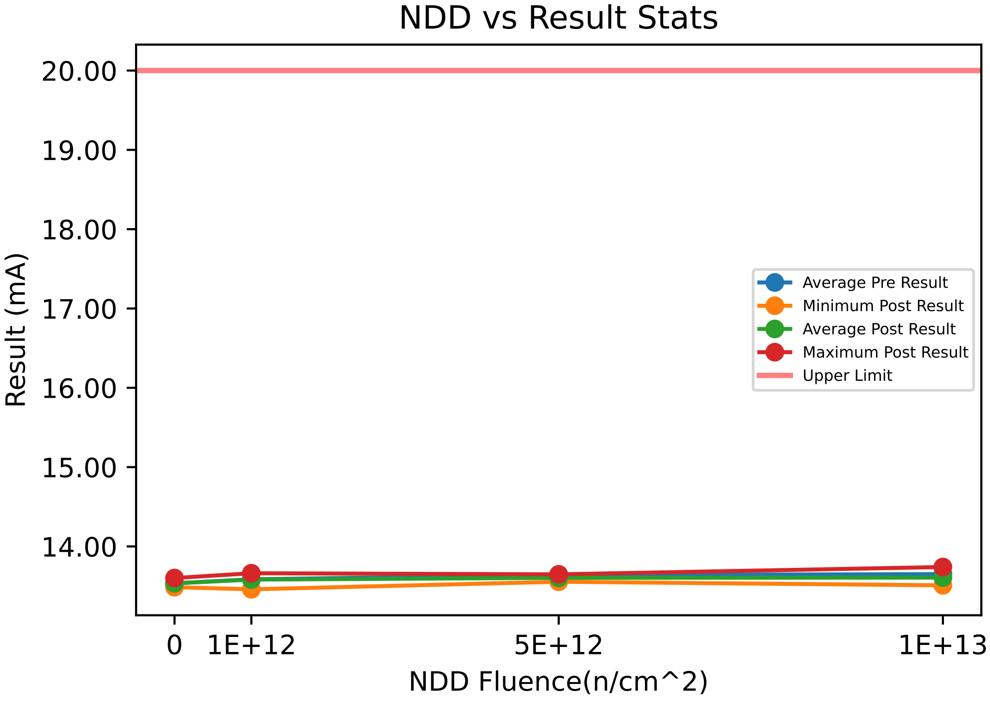
Test Results (Upper Limit = 13.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.8767	9.875	-0.0017
2	1e+12	NDD	9.7914	9.7921	0.0007
3	1e+12	NDD	9.9487	9.9461	-0.0026
4	1e+12	NDD	9.8878	9.8891	0.0013
5	5e+12	NDD	9.9542	9.9279	-0.0263
6	5e+12	NDD	9.9809	9.9502	-0.0307
7	5e+12	NDD	9.9831	9.9678	-0.0153
8	5e+12	NDD	9.9046	9.8743	-0.0303
9	1e+13	NDD	9.836	9.8122	-0.0238
10	1e+13	NDD	9.8261	9.7977	-0.0284
11	1e+13	NDD	10.002	9.9701	-0.0324
12	1e+13	NDD	10.05	10.003	-0.0477
13	0	CORRELATION	9.8389	9.8395	0.0006
14	0	CORRELATION	9.9133	9.9123	-0.001
15	0	CORRELATION	9.8046	9.8004	-0.0042

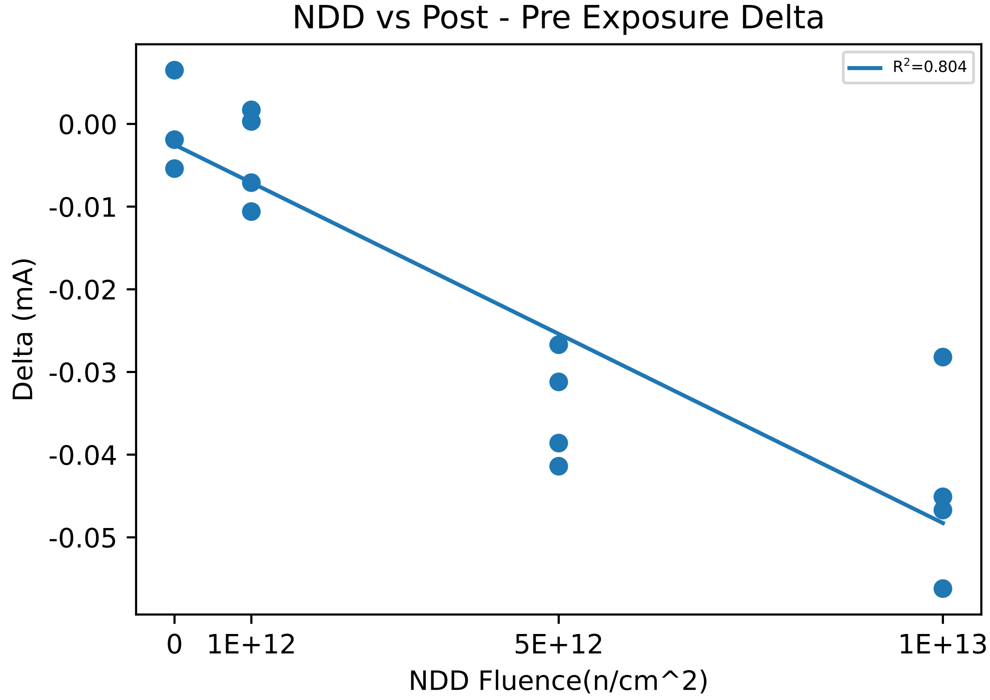
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8046	9.8523	9.9133	0.055569	9.8004	9.8507	9.9123	0.056789	-0.0042	-0.0015333	0.0006	0.002444
1e+12	9.7914	9.8761	9.9487	0.064761	9.7921	9.8756	9.9461	0.063574	-0.0026	-0.000575	0.0013	0.0018715
5e+12	9.9046	9.9557	9.9831	0.036511	9.8743	9.93	9.9678	0.040595	-0.0307	-0.02565	-0.0153	0.0071803
1e+13	9.8261	9.9287	10.05	0.11453	9.7977	9.8956	10.003	0.10573	-0.0477	-0.033075	-0.0238	0.010364

Device Test: 14.32 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_LDO



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

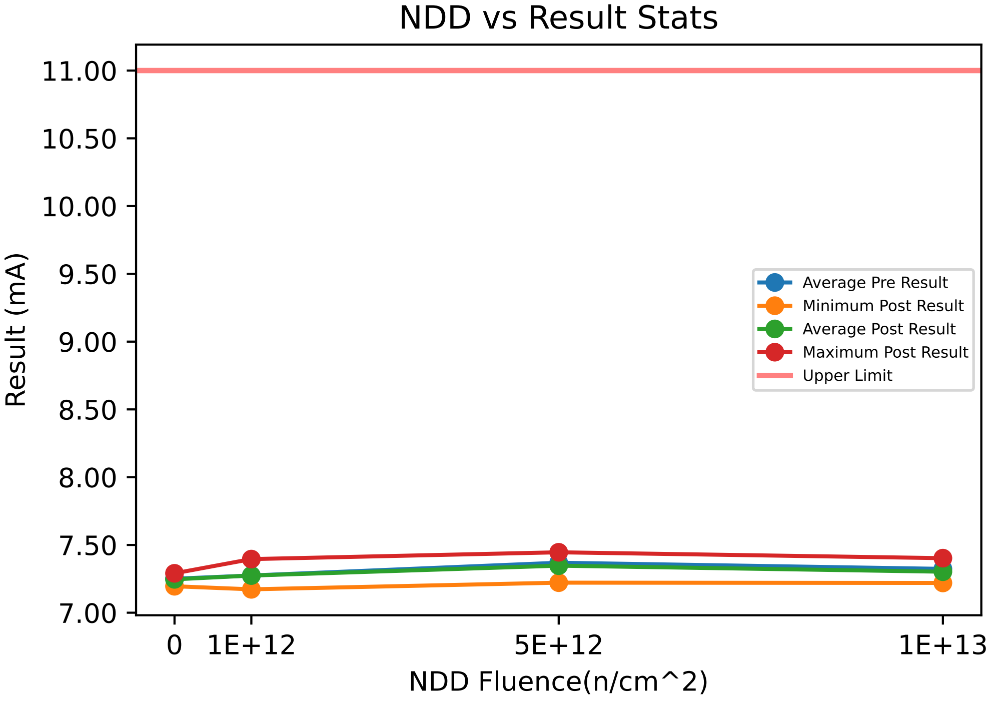
Test Results (Upper Limit = 20.0 (mA))

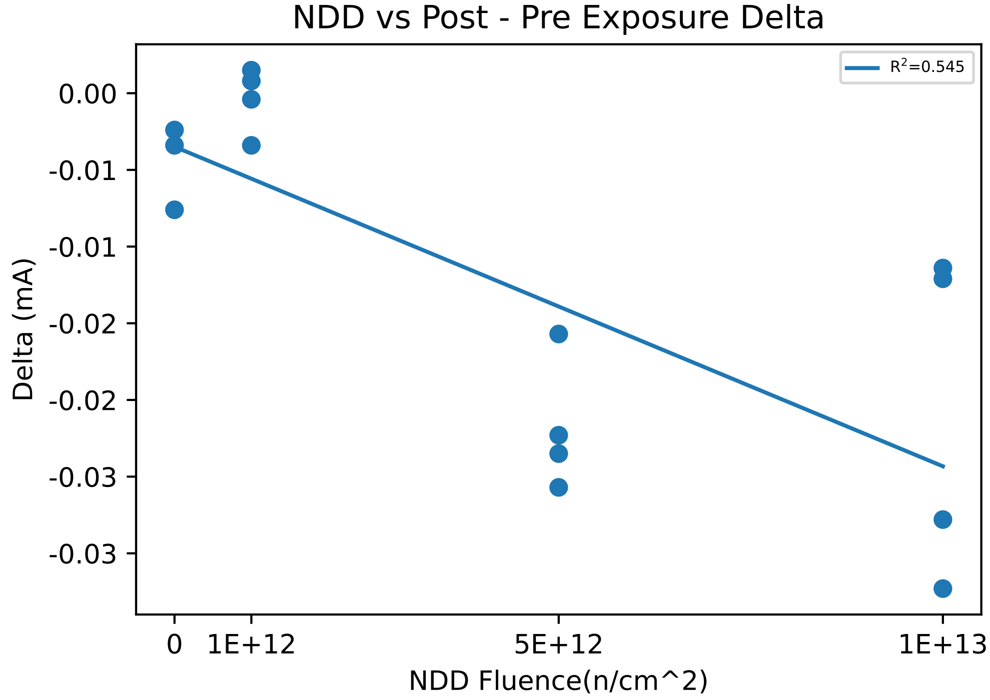
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	13.629	13.618	-0.0106
2	1e+12	NDD	13.459	13.459	0.0003
3	1e+12	NDD	13.66	13.662	0.0017
4	1e+12	NDD	13.596	13.589	-0.0071
5	5e+12	NDD	13.594	13.555	-0.0386
6	5e+12	NDD	13.675	13.648	-0.0267
7	5e+12	NDD	13.672	13.641	-0.0312
8	5e+12	NDD	13.614	13.572	-0.0414
9	1e+13	NDD	13.538	13.51	-0.0282
10	1e+13	NDD	13.566	13.521	-0.0451
11	1e+13	NDD	13.704	13.657	-0.0467
12	1e+13	NDD	13.796	13.74	-0.0562
13	0	CORRELATION	13.522	13.516	-0.0054
14	0	CORRELATION	13.604	13.602	-0.0019
15	0	CORRELATION	13.48	13.486	0.0065

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.48	13.535	13.604	0.06288	13.486	13.535	13.602	0.059794	-0.0054	-0.00026667	0.0065	0.0061158
1e+12	13.459	13.586	13.66	0.088575	13.459	13.582	13.662	0.087117	-0.0106	-0.003925	0.0017	0.0058914
5e+12	13.594	13.639	13.675	0.041245	13.555	13.604	13.648	0.047407	-0.0414	-0.034475	-0.0267	0.0067367
1e+13	13.538	13.651	13.796	0.12093	13.51	13.607	13.74	0.11114	-0.0562	-0.04405	-0.0282	0.011647

Device Test: 14.4 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





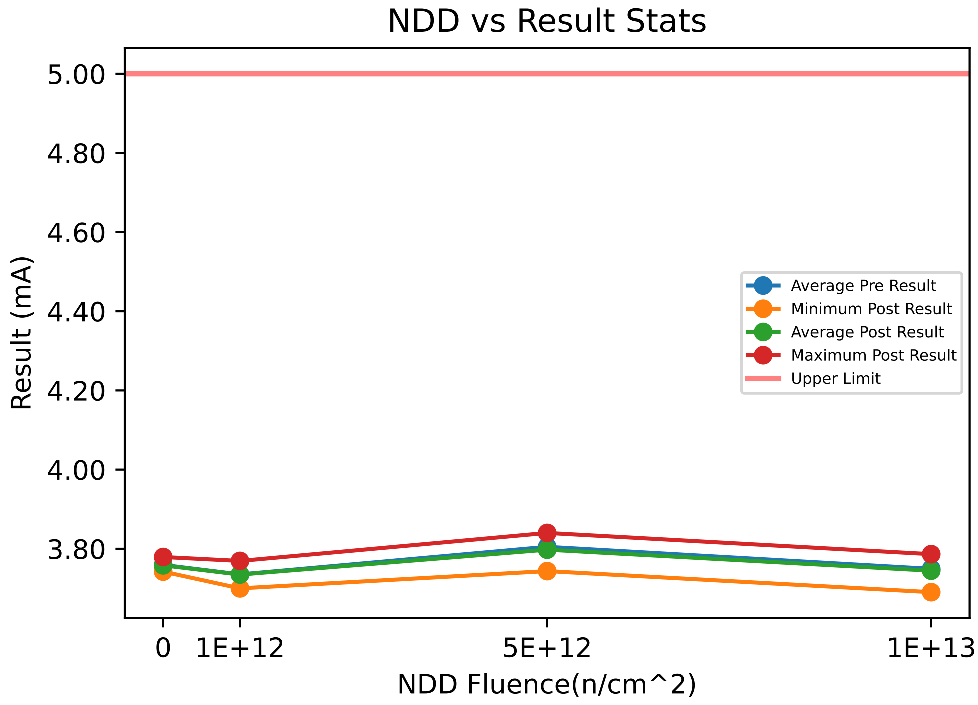
Test Results (Upper Limit = 11.0 (mA))

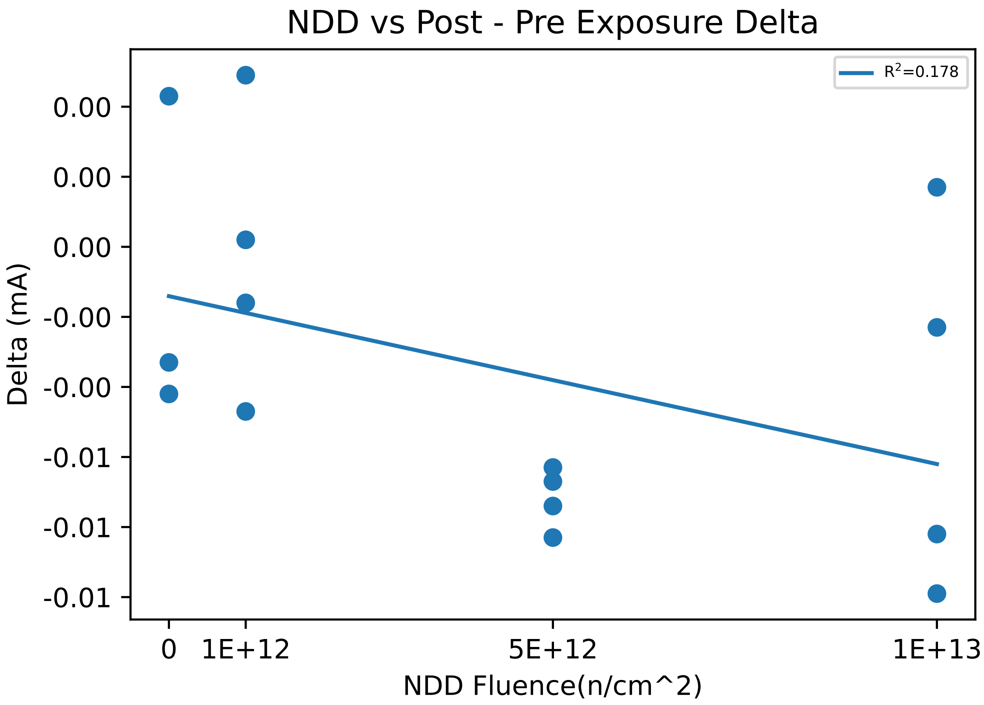
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.2442	7.2408	-0.0034
2	1e+12	NDD	7.1718	7.1726	0.0008
3	1e+12	NDD	7.3941	7.3956	0.0015
4	1e+12	NDD	7.2881	7.2877	-0.0004
5	5e+12	NDD	7.4693	7.4458	-0.0235
6	5e+12	NDD	7.4044	7.3821	-0.0223
7	5e+12	NDD	7.3542	7.3385	-0.0157
8	5e+12	NDD	7.2474	7.2217	-0.0257
9	1e+13	NDD	7.2529	7.2415	-0.0114
10	1e+13	NDD	7.2318	7.2197	-0.0121
11	1e+13	NDD	7.3743	7.3465	-0.0278
12	1e+13	NDD	7.4348	7.4025	-0.0323
13	0	CORRELATION	7.2554	7.253	-0.0024
14	0	CORRELATION	7.2982	7.2906	-0.0076
15	0	CORRELATION	7.1986	7.1952	-0.0034

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1986	7.2507	7.2982	0.049964	7.1952	7.2463	7.2906	0.048055	-0.0076	-0.0044667	-0.0024	0.0027592
1e+12	7.1718	7.2745	7.3941	0.093013	7.1726	7.2742	7.3956	0.093734	-0.0034	-0.000375	0.0015	0.0021639
5e+12	7.2474	7.3688	7.4693	0.093664	7.2217	7.347	7.4458	0.094456	-0.0257	-0.0218	-0.0157	0.0043035
1e+13	7.2318	7.3235	7.4348	0.097231	7.2197	7.3026	7.4025	0.086627	-0.0323	-0.0209	-0.0114	0.010728

Device Test: 14.5 ISTART|STARTUP CURRENT/IN/3.5/3.5/0/0/4.5/500kHz//@I_START


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

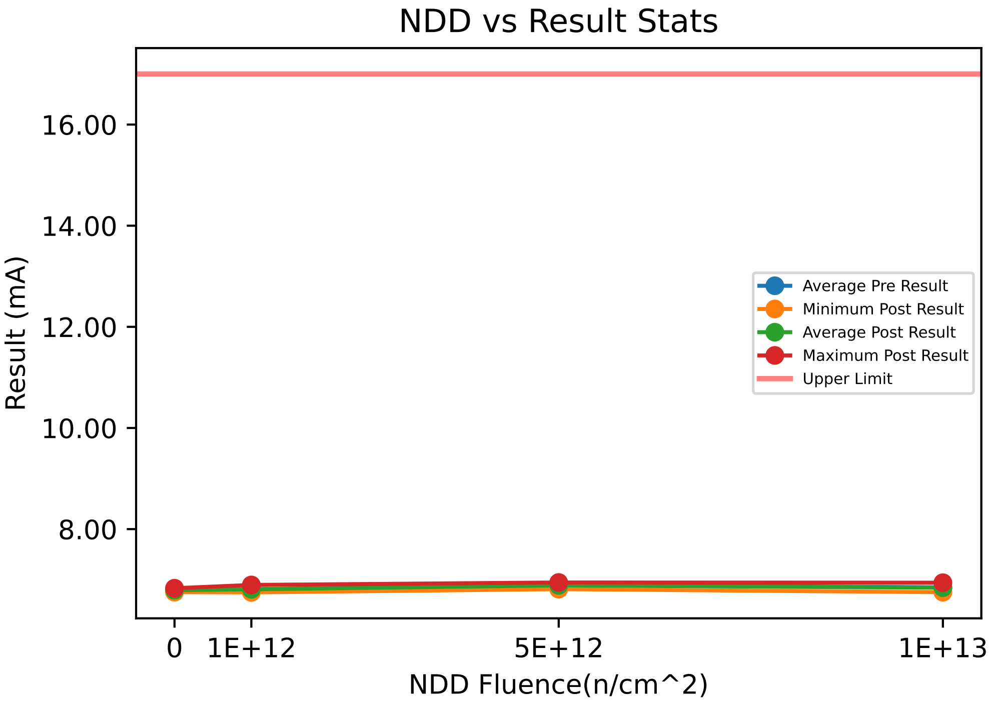
Test Results (Upper Limit = 5.0 (mA))

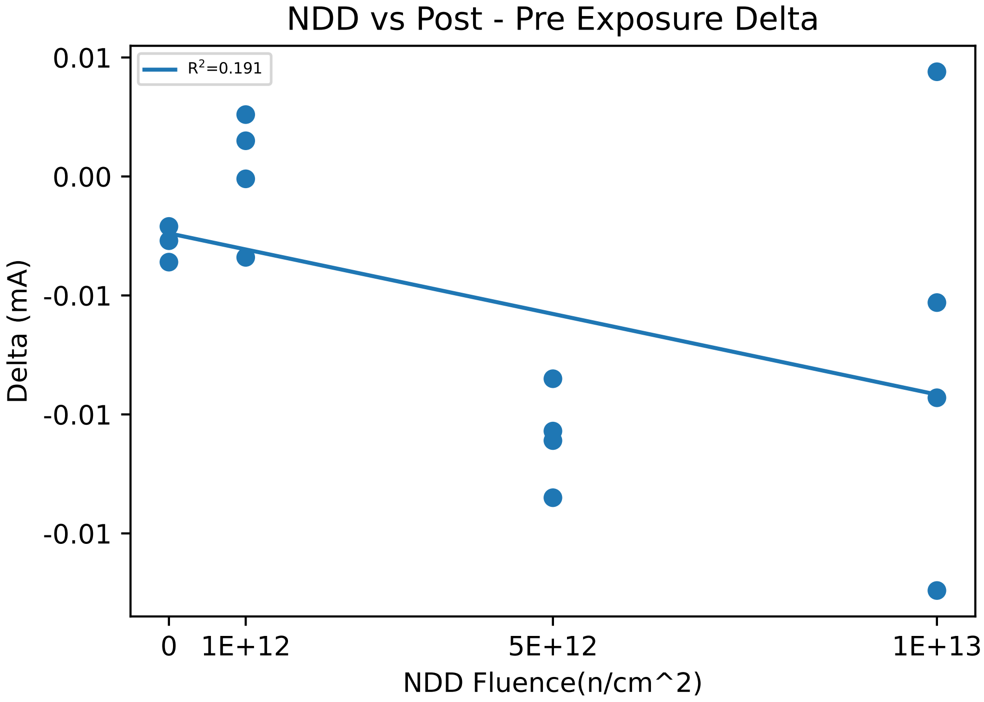
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7047	3.7	-0.0047
2	1e+12	NDD	3.7214	3.7216	0.0002
3	1e+12	NDD	3.7644	3.7693	0.0049
4	1e+12	NDD	3.7503	3.7487	-0.0016
5	5e+12	NDD	3.8463	3.84	-0.0063
6	5e+12	NDD	3.8131	3.8057	-0.0074
7	5e+12	NDD	3.8099	3.8016	-0.0083
8	5e+12	NDD	3.7503	3.7436	-0.0067
9	1e+13	NDD	3.7215	3.7192	-0.0023
10	1e+13	NDD	3.6887	3.6904	0.0017
11	1e+13	NDD	3.7907	3.7825	-0.0082
12	1e+13	NDD	3.7963	3.7864	-0.0099
13	0	CORRELATION	3.7561	3.7528	-0.0033
14	0	CORRELATION	3.7749	3.7792	0.0043
15	0	CORRELATION	3.7465	3.7423	-0.0042

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7465	3.7592	3.7749	0.014446	3.7423	3.7581	3.7792	0.019012	-0.0042	-0.0010667	0.0043	0.0046694
1e+12	3.7047	3.7352	3.7644	0.027088	3.7	3.7349	3.7693	0.030379	-0.0047	-0.0003	0.0049	0.0040141
5e+12	3.7503	3.8049	3.8463	0.039947	3.7436	3.7977	3.84	0.03998	-0.0083	-0.007175	-0.0063	0.00087702
1e+13	3.6887	3.7493	3.7963	0.052815	3.6904	3.7446	3.7864	0.047492	-0.0099	-0.004675	0.0017	0.0053544

Device Test: 14.6 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_ACT_500K_NOLOAD





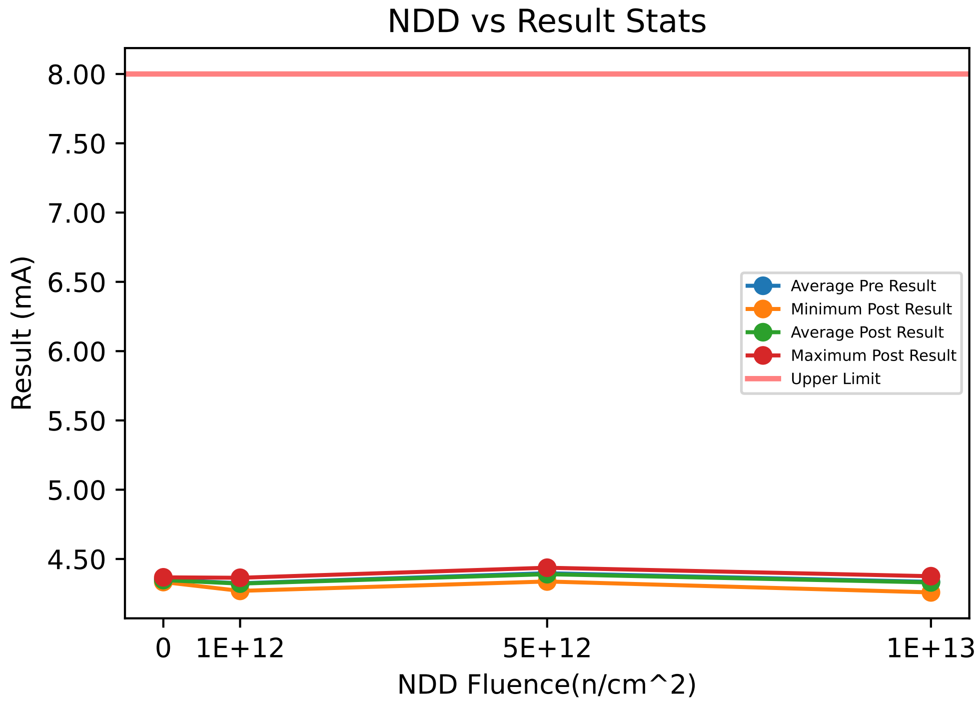
Test Results (Upper Limit = 17.0 (mA))

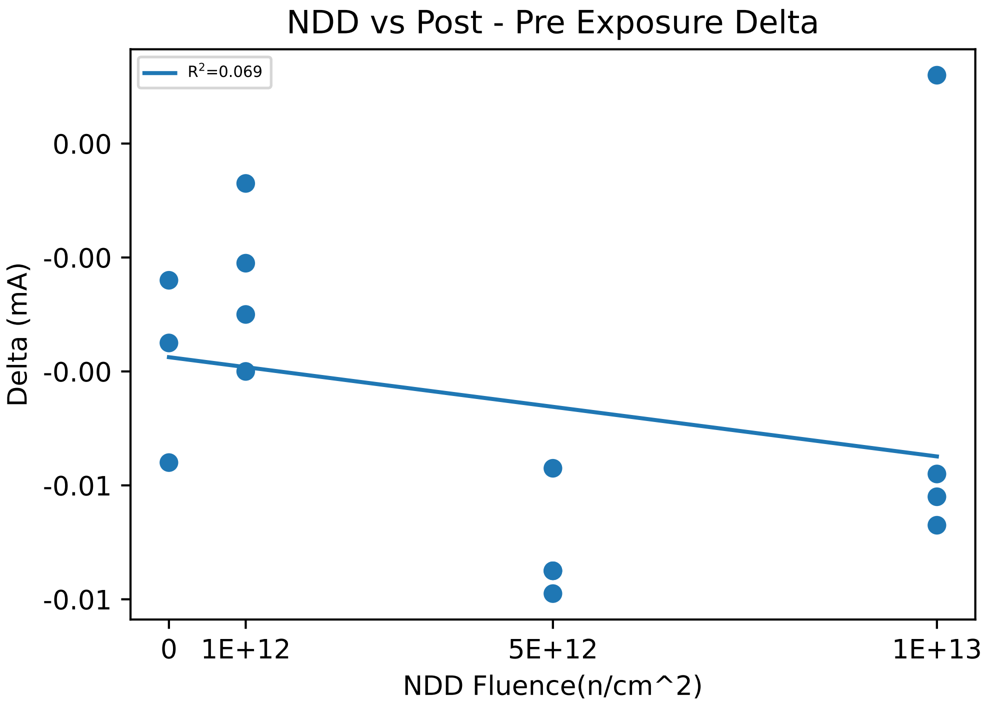
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.7881	6.7847	-0.0034
2	1e+12	NDD	6.746	6.7486	0.0026
3	1e+12	NDD	6.8942	6.8957	0.0015
4	1e+12	NDD	6.8114	6.8113	-0.0001
5	5e+12	NDD	6.9558	6.9447	-0.0111
6	5e+12	NDD	6.9255	6.912	-0.0135
7	5e+12	NDD	6.8902	6.8817	-0.0085
8	5e+12	NDD	6.8236	6.8129	-0.0107
9	1e+13	NDD	6.7729	6.7773	0.0044
10	1e+13	NDD	6.758	6.7527	-0.0053
11	1e+13	NDD	6.9028	6.8935	-0.0093
12	1e+13	NDD	6.9576	6.9402	-0.0174
13	0	CORRELATION	6.7993	6.7972	-0.0021
14	0	CORRELATION	6.8346	6.831	-0.0036
15	0	CORRELATION	6.7565	6.7538	-0.0027

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7565	6.7968	6.8346	0.03911	6.7538	6.794	6.831	0.038699	-0.0036	-0.0028	-0.0021	0.00075498
1e+12	6.746	6.8099	6.8942	0.062362	6.7486	6.8101	6.8957	0.0626	-0.0034	0.00015	0.0026	0.0026134
5e+12	6.8236	6.8988	6.9558	0.056836	6.8129	6.8878	6.9447	0.056186	-0.0135	-0.01095	-0.0085	0.0020486
1e+13	6.758	6.8478	6.9576	0.097903	6.7527	6.8409	6.9402	0.09028	-0.0174	-0.0069	0.0044	0.0090602

Device Test: 14.7 IDD_DIS|STANDBY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_DIS





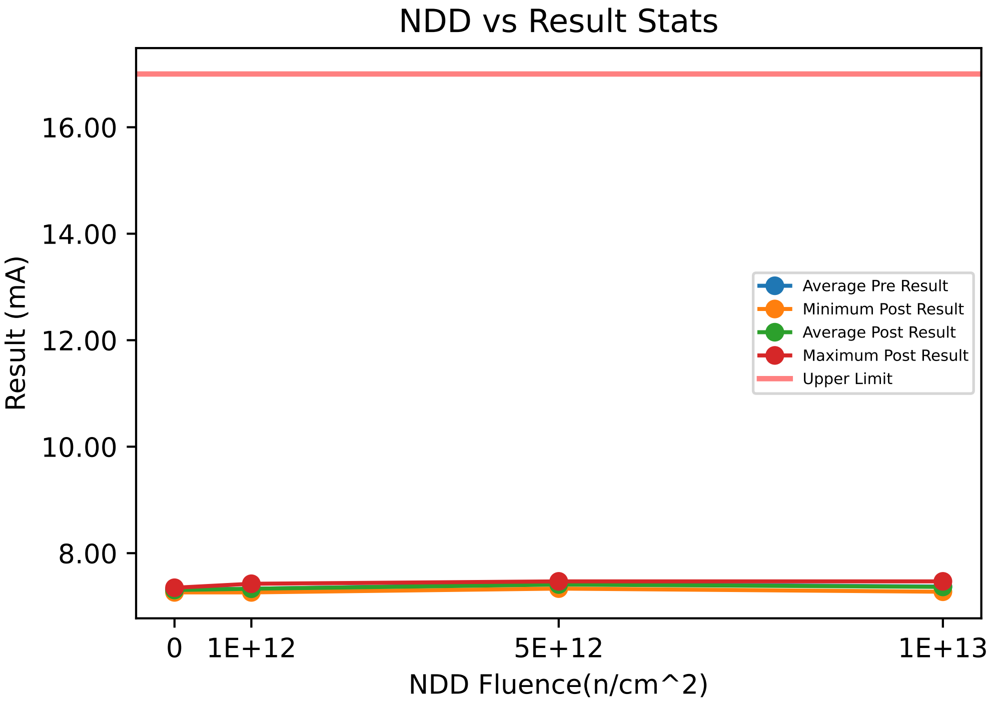
Test Results (Upper Limit = 8.0 (mA))

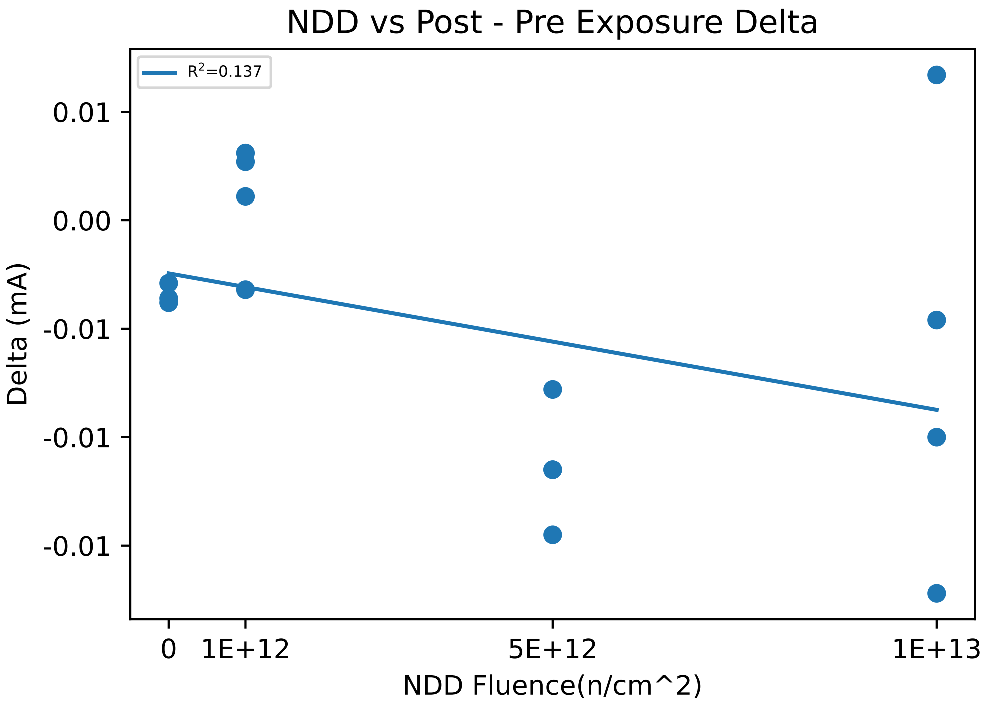
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.2739	4.2699	-0.004
2	1e+12	NDD	4.3167	4.3146	-0.0021
3	1e+12	NDD	4.3651	4.3644	-0.0007
4	1e+12	NDD	4.3434	4.3404	-0.003
5	5e+12	NDD	4.4445	4.437	-0.0075
6	5e+12	NDD	4.4009	4.393	-0.0079
7	5e+12	NDD	4.4009	4.3934	-0.0075
8	5e+12	NDD	4.3433	4.3376	-0.0057
9	1e+13	NDD	4.3153	4.3165	0.0012
10	1e+13	NDD	4.2647	4.2589	-0.0058
11	1e+13	NDD	4.3819	4.3757	-0.0062
12	1e+13	NDD	4.3788	4.3721	-0.0067
13	0	CORRELATION	4.3479	4.3423	-0.0056
14	0	CORRELATION	4.3711	4.3676	-0.0035
15	0	CORRELATION	4.336	4.3336	-0.0024

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.336	4.3517	4.3711	0.017851	4.3336	4.3478	4.3676	0.017662	-0.0056	-0.0038333	-0.0024	0.0016258
1e+12	4.2739	4.3248	4.3651	0.03927	4.2699	4.3223	4.3644	0.040435	-0.004	-0.00245	-0.0007	0.0014012
5e+12	4.3433	4.3974	4.4445	0.041512	4.3376	4.3902	4.437	0.040723	-0.0079	-0.00715	-0.0057	0.00098489
1e+13	4.2647	4.3352	4.3819	0.056119	4.2589	4.3308	4.3757	0.055063	-0.0067	-0.004375	0.0012	0.0037349

Device Test: 14.8 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





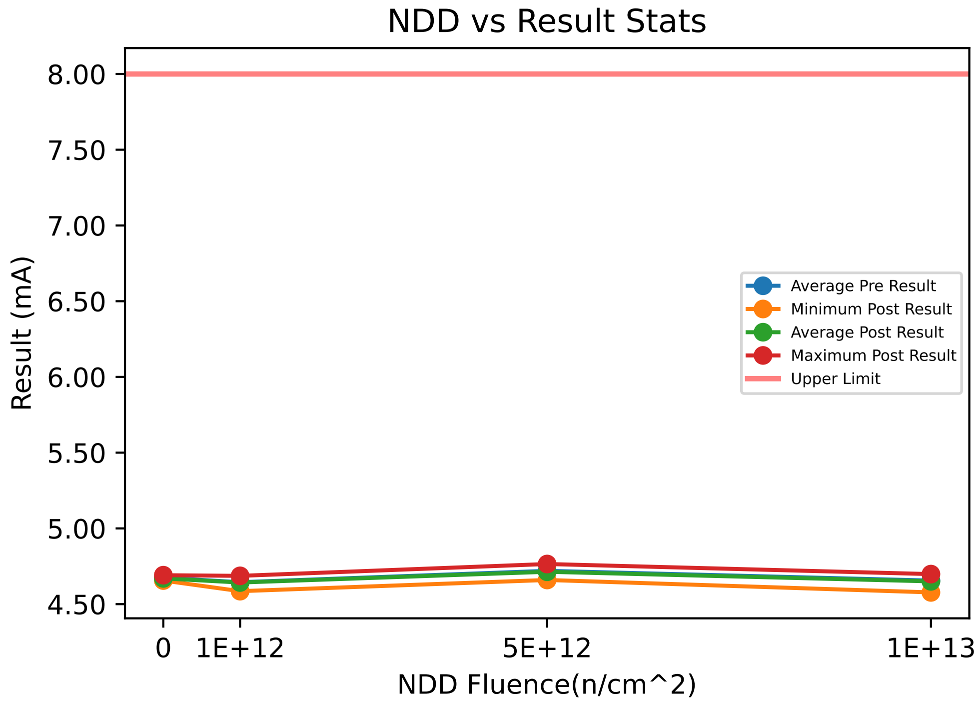
Test Results (Upper Limit = 17.0 (mA))

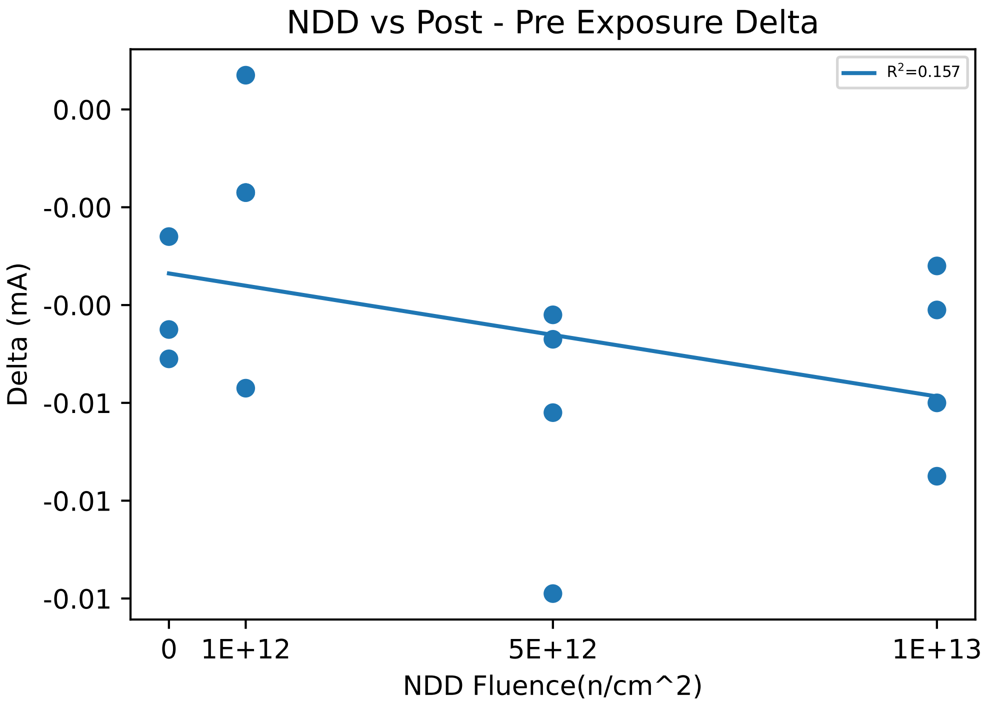
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.309	7.3058	-0.0032
2	1e+12	NDD	7.2603	7.263	0.0027
3	1e+12	NDD	7.4221	7.4252	0.0031
4	1e+12	NDD	7.3312	7.3323	0.0011
5	5e+12	NDD	7.4816	7.4701	-0.0115
6	5e+12	NDD	7.4481	7.4336	-0.0145
7	5e+12	NDD	7.4133	7.4055	-0.0078
8	5e+12	NDD	7.3459	7.3344	-0.0115
9	1e+13	NDD	7.2904	7.2971	0.0067
10	1e+13	NDD	7.28	7.2754	-0.0046
11	1e+13	NDD	7.431	7.421	-0.01
12	1e+13	NDD	7.4872	7.47	-0.0172
13	0	CORRELATION	7.3148	7.3112	-0.0036
14	0	CORRELATION	7.354	7.3502	-0.0038
15	0	CORRELATION	7.2661	7.2632	-0.0029

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2661	7.3116	7.354	0.044035	7.2632	7.3082	7.3502	0.043578	-0.0038	-0.0034333	-0.0029	0.00047258
1e+12	7.2603	7.3307	7.4221	0.067777	7.263	7.3316	7.4252	0.068637	-0.0032	0.000925	0.0031	0.0028826
5e+12	7.3459	7.4222	7.4816	0.058023	7.3344	7.4109	7.4701	0.05745	-0.0145	-0.011325	-0.0078	0.0027427
1e+13	7.28	7.3721	7.4872	0.10308	7.2754	7.3659	7.47	0.09451	-0.0172	-0.006275	0.0067	0.010073

Device Test: 14.9 IDD_DIS|STANDBY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_DIS


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

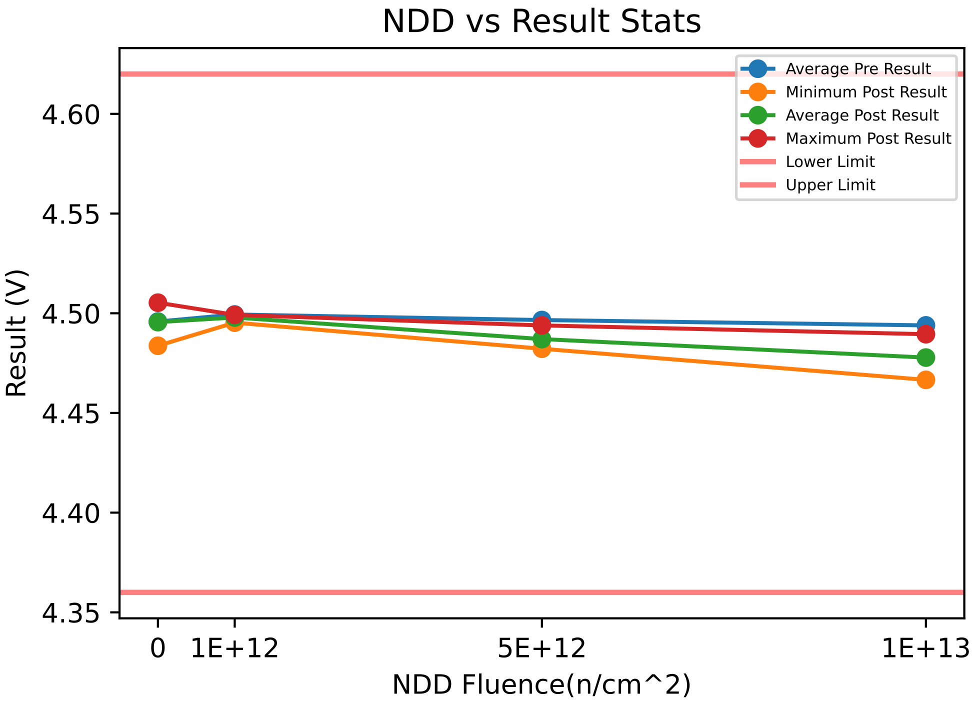
Test Results (Upper Limit = 8.0 (mA))

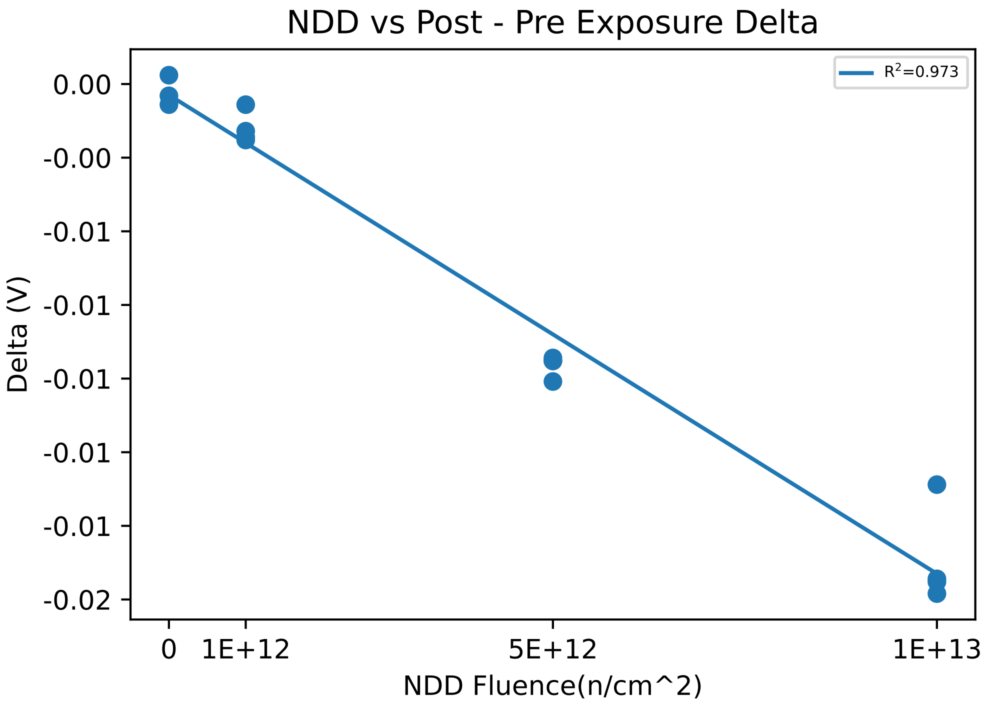
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.5913	4.5856	-0.0057
2	1e+12	NDD	4.6379	4.6386	0.0007
3	1e+12	NDD	4.6884	4.6867	-0.0017
4	1e+12	NDD	4.6615	4.6598	-0.0017
5	5e+12	NDD	4.7696	4.7649	-0.0047
6	5e+12	NDD	4.7192	4.715	-0.0042
7	5e+12	NDD	4.725	4.7151	-0.0099
8	5e+12	NDD	4.6657	4.6595	-0.0062
9	1e+13	NDD	4.637	4.6338	-0.0032
10	1e+13	NDD	4.5816	4.5775	-0.0041
11	1e+13	NDD	4.7043	4.6983	-0.006
12	1e+13	NDD	4.6992	4.6917	-0.0075
13	0	CORRELATION	4.6682	4.6631	-0.0051
14	0	CORRELATION	4.6937	4.6911	-0.0026
15	0	CORRELATION	4.6602	4.6557	-0.0045

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6602	4.674	4.6937	0.017495	4.6557	4.67	4.6911	0.018672	-0.0051	-0.0040667	-0.0026	0.0013051
1e+12	4.5913	4.6448	4.6884	0.041189	4.5856	4.6427	4.6867	0.042839	-0.0057	-0.0021	0.0007	0.0026533
5e+12	4.6657	4.7199	4.7696	0.042561	4.6595	4.7136	4.7649	0.043061	-0.0099	-0.00625	-0.0042	0.0025775
1e+13	4.5816	4.6555	4.7043	0.058007	4.5775	4.6503	4.6983	0.056539	-0.0075	-0.0052	-0.0032	0.001927

Device Test: 15.1 VLDO|V_VLDO/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_4P5





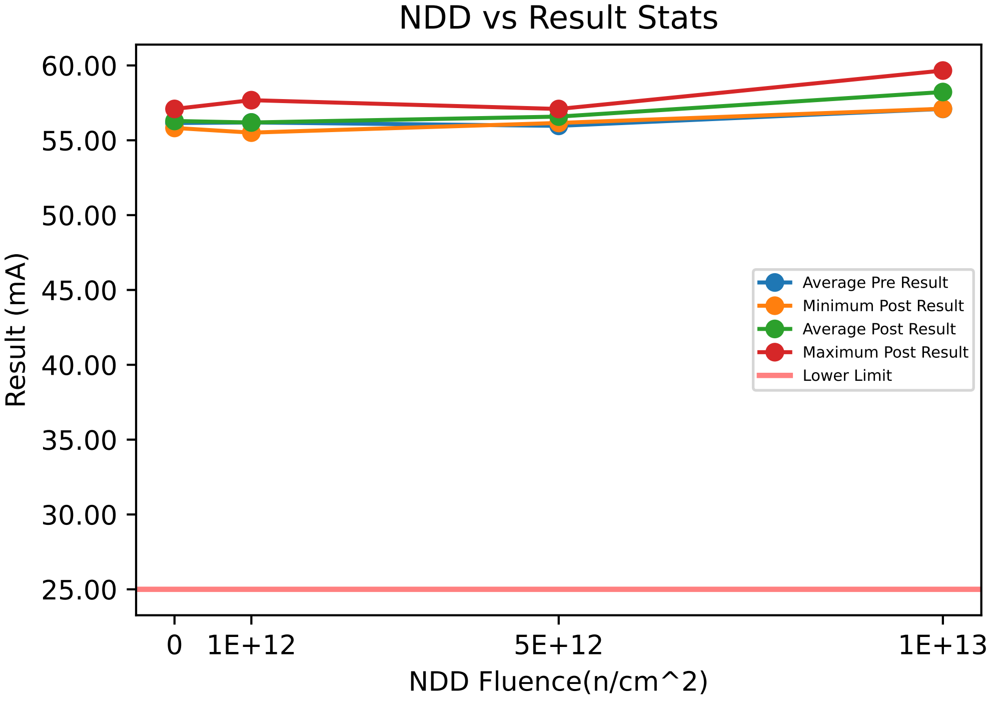
Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

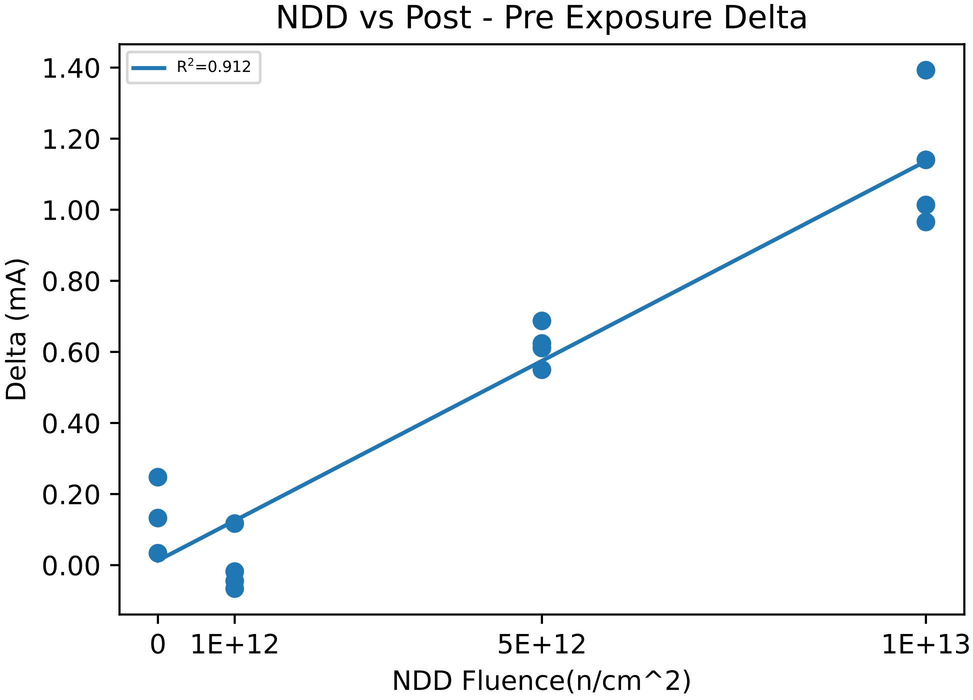
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.4999	4.498	-0.0019
2	1e+12	NDD	4.496	4.4953	-0.0007
3	1e+12	NDD	4.501	4.4992	-0.0018
4	1e+12	NDD	4.5006	4.499	-0.0016
5	5e+12	NDD	4.4975	4.4874	-0.0101
6	5e+12	NDD	4.5033	4.4939	-0.0094
7	5e+12	NDD	4.4941	4.4847	-0.0094
8	5e+12	NDD	4.4915	4.4822	-0.0093
9	1e+13	NDD	4.4834	4.4666	-0.0168
10	1e+13	NDD	4.4898	4.4725	-0.0173
11	1e+13	NDD	4.4961	4.4825	-0.0136
12	1e+13	NDD	4.5064	4.4895	-0.0169
13	0	CORRELATION	4.4844	4.4837	-0.0007
14	0	CORRELATION	4.4974	4.4977	0.0003
15	0	CORRELATION	4.5057	4.5053	-0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4844	4.4958	4.5057	0.010736	4.4837	4.4956	4.5053	0.010957	-0.0007	-0.00026667	0.0003	0.00051316
1e+12	4.496	4.4994	4.501	0.0022955	4.4953	4.4979	4.4992	0.0017951	-0.0019	-0.0015	-0.0007	0.00054772
5e+12	4.4915	4.4966	4.5033	0.0050977	4.4822	4.487	4.4939	0.0050362	-0.0101	-0.00955	-0.0093	0.00036968
1e+13	4.4834	4.4939	4.5064	0.0098005	4.4666	4.4778	4.4895	0.010206	-0.0173	-0.01615	-0.0136	0.0017137

Device Test: 15.10 VLDO|ILIM_VLDO_SWEEP/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_ILIM_5_PLUS_0P5





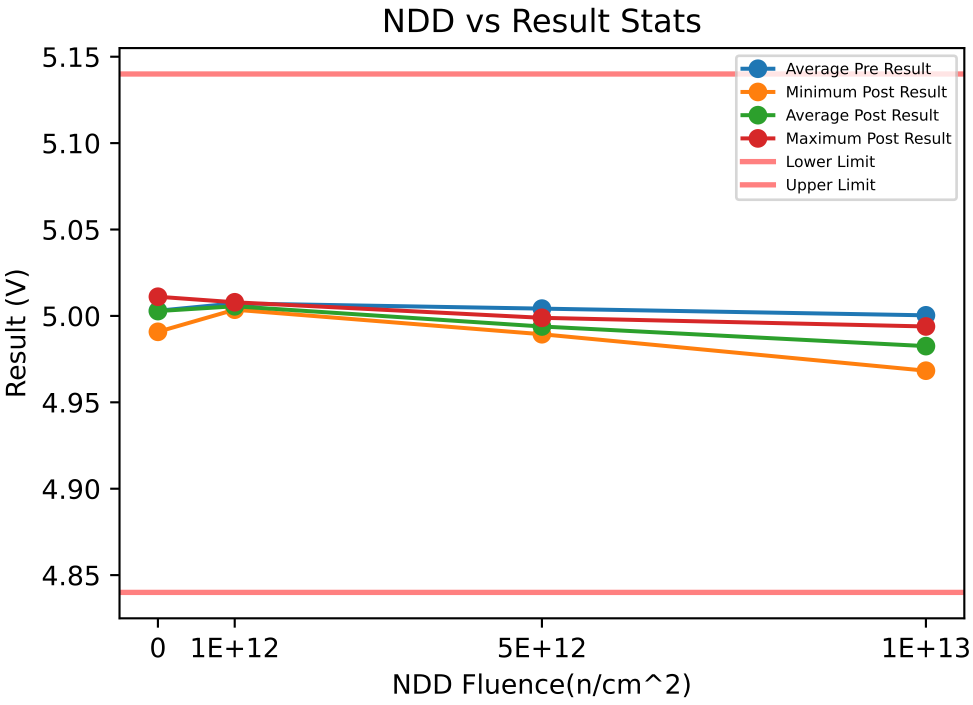
Test Results (Lower Limit = 25.0 (mA))

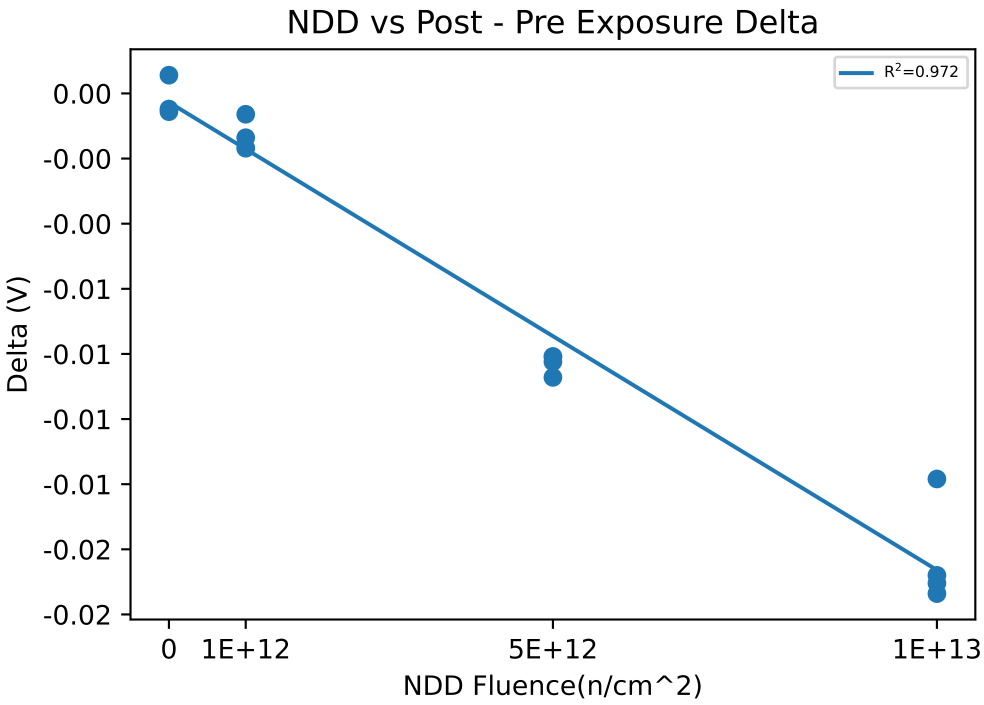
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	57.698	57.68	-0.0181
2	1e+12	NDD	55.577	55.511	-0.066
3	1e+12	NDD	55.616	55.572	-0.0445
4	1e+12	NDD	55.873	55.99	0.117
5	5e+12	NDD	56.013	56.7	0.6872
6	5e+12	NDD	55.828	56.377	0.5498
7	5e+12	NDD	55.535	56.159	0.6238
8	5e+12	NDD	56.48	57.091	0.611
9	1e+13	NDD	57.452	58.465	1.0135
10	1e+13	NDD	58.266	59.659	1.3927
11	1e+13	NDD	56.699	57.665	0.9656
12	1e+13	NDD	55.966	57.107	1.1404
13	0	CORRELATION	56.846	57.094	0.2475
14	0	CORRELATION	55.691	55.824	0.1325
15	0	CORRELATION	55.918	55.951	0.0336

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	55.691	56.152	56.846	0.61214	55.824	56.29	57.094	0.69945	0.0336	0.13787	0.2475	0.10705
1e+12	55.577	56.191	57.698	1.013	55.511	56.188	57.68	1.0169	-0.066	-0.0029	0.117	0.082299
5e+12	55.535	55.964	56.48	0.39642	56.159	56.582	57.091	0.40584	0.5498	0.61795	0.6872	0.05634
1e+13	55.966	57.096	58.266	0.98803	57.107	58.224	59.659	1.1071	0.9656	1.128	1.3927	0.19123

Device Test: 15.11 VLDO|V_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_5





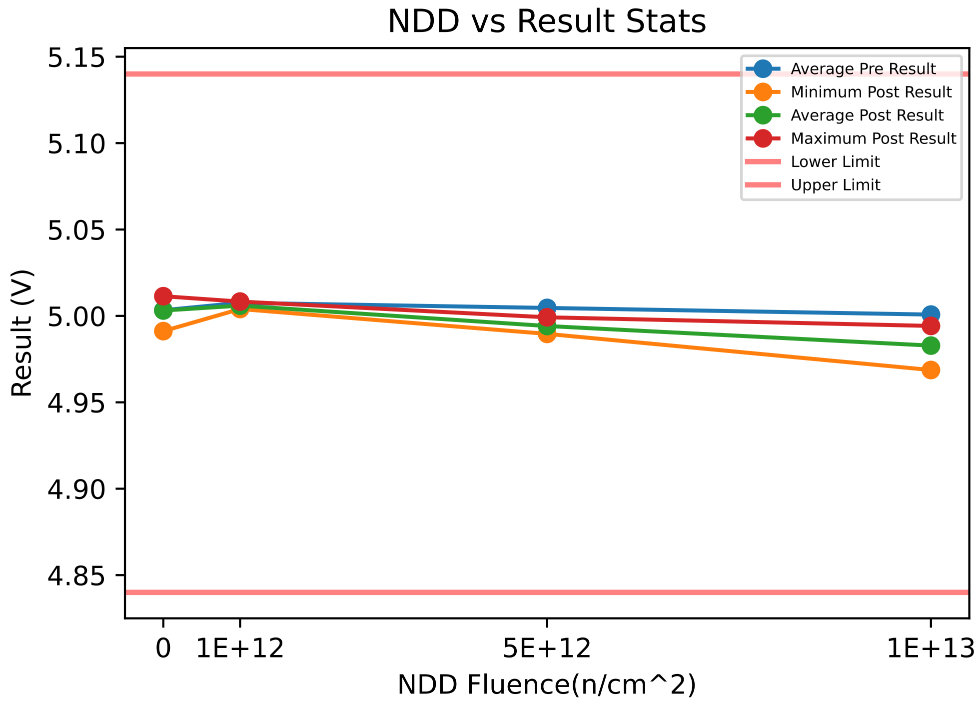
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

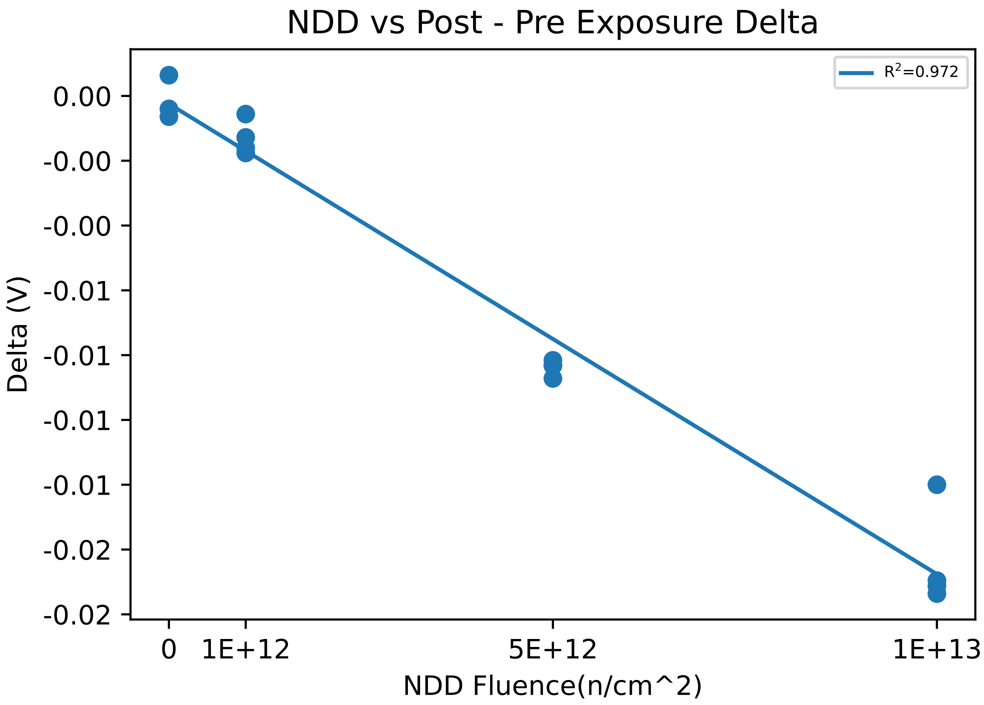
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.0086	5.0065	-0.0021
2	1e+12	NDD	5.0044	5.0036	-0.0008
3	1e+12	NDD	5.0064	5.0043	-0.0021
4	1e+12	NDD	5.0096	5.0079	-0.0017
5	5e+12	NDD	5.006	4.9951	-0.0109
6	5e+12	NDD	5.0092	4.9989	-0.0103
7	5e+12	NDD	5.0022	4.9921	-0.0101
8	5e+12	NDD	4.9995	4.9894	-0.0101
9	1e+13	NDD	4.9871	4.9683	-0.0188
10	1e+13	NDD	4.9973	4.9781	-0.0192
11	1e+13	NDD	5.0046	4.9898	-0.0148
12	1e+13	NDD	5.0124	4.9939	-0.0185
13	0	CORRELATION	4.9914	4.9908	-0.0006
14	0	CORRELATION	5.0058	5.0065	0.0007
15	0	CORRELATION	5.0118	5.0111	-0.0007

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9914	5.003	5.0118	0.010484	4.9908	5.0028	5.0111	0.010644	-0.0007	-0.0002	0.0007	0.00078102
1e+12	5.0044	5.0072	5.0096	0.0023231	5.0036	5.0056	5.0079	0.0019822	-0.0021	-0.001675	-0.0008	0.00061305
5e+12	4.9995	5.0042	5.0092	0.0042555	4.9894	4.9939	4.9989	0.0040795	-0.0109	-0.01035	-0.0101	0.00037859
1e+13	4.9871	5.0004	5.0124	0.010772	4.9683	4.9825	4.9939	0.011608	-0.0192	-0.017825	-0.0148	0.002037

Device Test: 15.12 VLDO|V_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_5





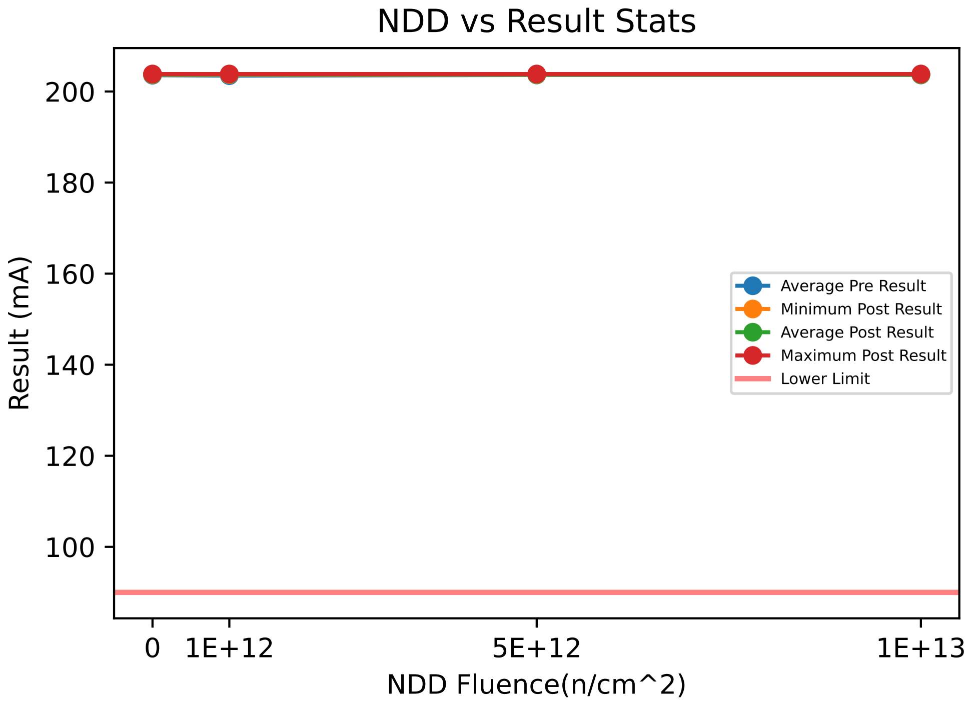
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

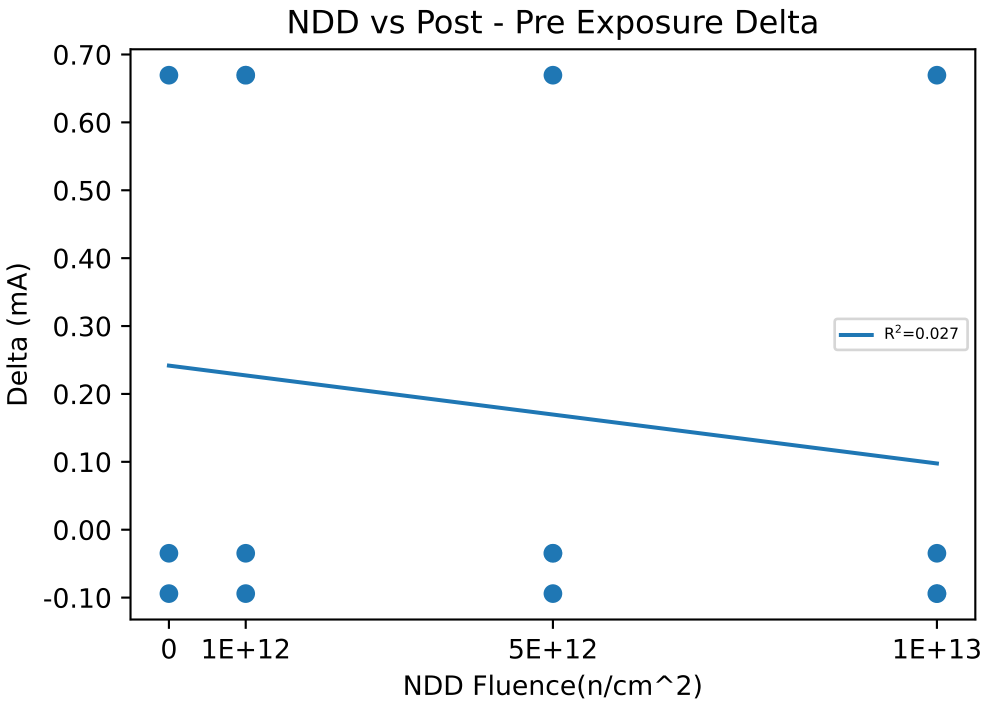
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.009	5.0068	-0.0022
2	1e+12	NDD	5.0047	5.004	-0.0007
3	1e+12	NDD	5.0067	5.0047	-0.002
4	1e+12	NDD	5.0099	5.0083	-0.0016
5	5e+12	NDD	5.0063	4.9954	-0.0109
6	5e+12	NDD	5.0096	4.9992	-0.0104
7	5e+12	NDD	5.0026	4.9924	-0.0102
8	5e+12	NDD	5	4.9896	-0.0104
9	1e+13	NDD	4.9876	4.9687	-0.0189
10	1e+13	NDD	4.9976	4.9784	-0.0192
11	1e+13	NDD	5.005	4.99	-0.015
12	1e+13	NDD	5.0129	4.9942	-0.0187
13	0	CORRELATION	4.9917	4.9912	-0.0005
14	0	CORRELATION	5.006	5.0068	0.0008
15	0	CORRELATION	5.0122	5.0114	-0.0008

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9917	5.0033	5.0122	0.010513	4.9912	5.0031	5.0114	0.010587	-0.0008	-0.00016667	0.0008	0.00085049
1e+12	5.0047	5.0076	5.0099	0.0023429	5.004	5.006	5.0083	0.0019672	-0.0022	-0.001625	-0.0007	0.00066521
5e+12	5	5.0046	5.0096	0.0042051	4.9896	4.9942	4.9992	0.0041162	-0.0109	-0.010475	-0.0102	0.00029861
1e+13	4.9876	5.0008	5.0129	0.010778	4.9687	4.9828	4.9942	0.011547	-0.0192	-0.01795	-0.015	0.0019774

Device Test: 15.13 VLDO|ILIM_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_ILIM_5_7





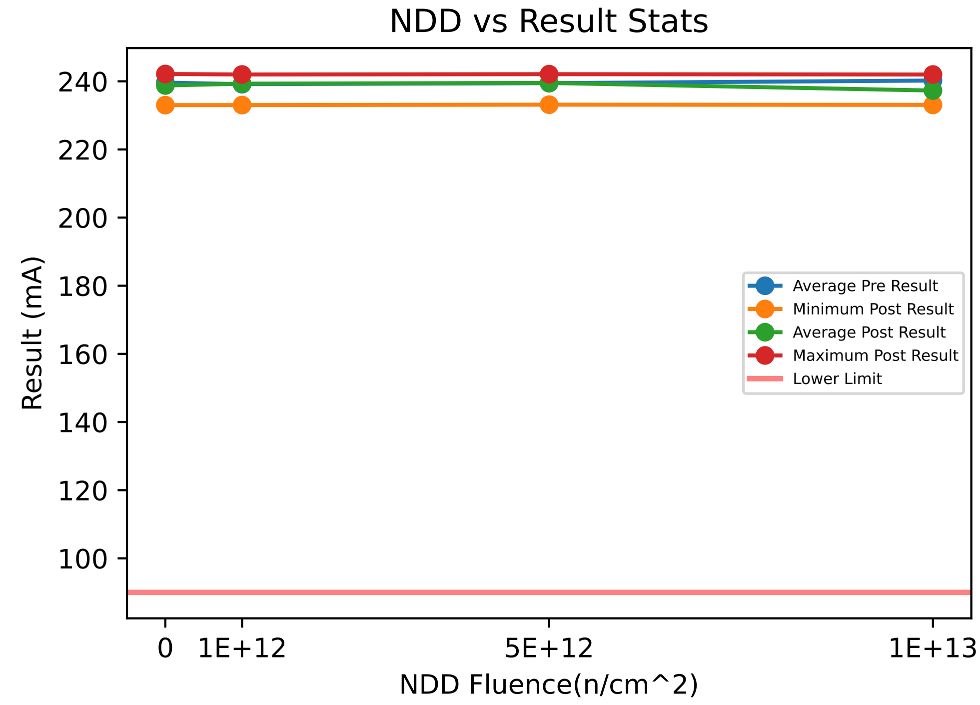
Test Results (Lower Limit = 90.0 (mA))

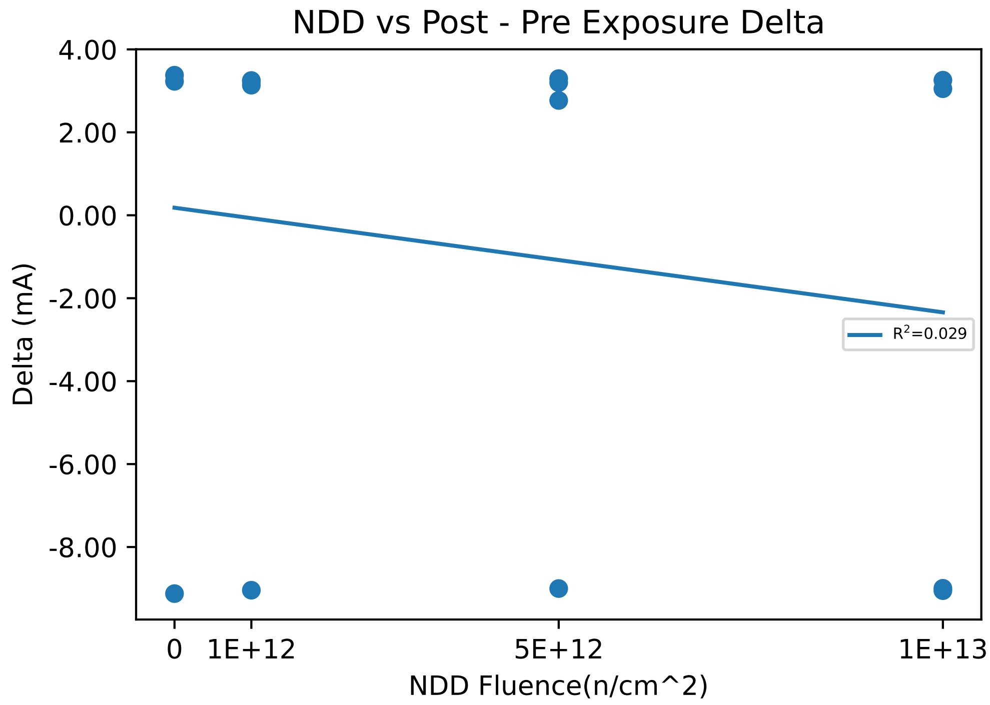
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	203.18	203.84	0.6695
2	1e+12	NDD	203.78	203.75	-0.0347
3	1e+12	NDD	203.79	203.69	-0.0941
4	1e+12	NDD	203.18	203.84	0.6695
5	5e+12	NDD	203.78	203.75	-0.0347
6	5e+12	NDD	203.79	203.69	-0.0941
7	5e+12	NDD	203.18	203.84	0.6695
8	5e+12	NDD	203.78	203.75	-0.0347
9	1e+13	NDD	203.79	203.69	-0.0941
10	1e+13	NDD	203.18	203.84	0.6695
11	1e+13	NDD	203.78	203.75	-0.0347
12	1e+13	NDD	203.79	203.69	-0.0941
13	0	CORRELATION	203.18	203.84	0.6695
14	0	CORRELATION	203.78	203.75	-0.0347
15	0	CORRELATION	203.79	203.69	-0.0941

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	203.18	203.58	203.79	0.35164	203.69	203.76	203.84	0.077132	-0.0941	0.18023	0.6695	0.42476
1e+12	203.18	203.48	203.79	0.35164	203.69	203.78	203.84	0.075486	-0.0941	0.30255	0.6695	0.42441
5e+12	203.18	203.63	203.79	0.30416	203.69	203.76	203.84	0.063375	-0.0941	0.1265	0.6695	0.36308
1e+13	203.18	203.63	203.79	0.30491	203.69	203.74	203.84	0.071825	-0.0941	0.11165	0.6695	0.37295

Device Test: 15.14 VLDO|ILIM_VLDO_SWEEP/VLDO/14/14/0/0/5/500kHz//@V_LDO_ILIM_5_7





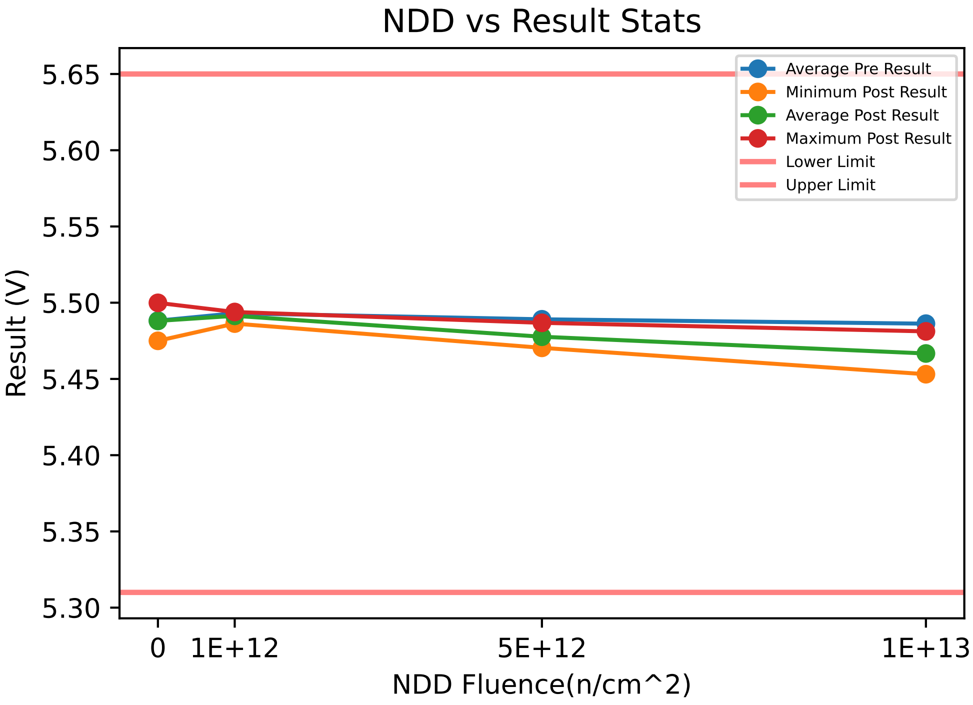
Test Results (Lower Limit = 90.0 (mA))

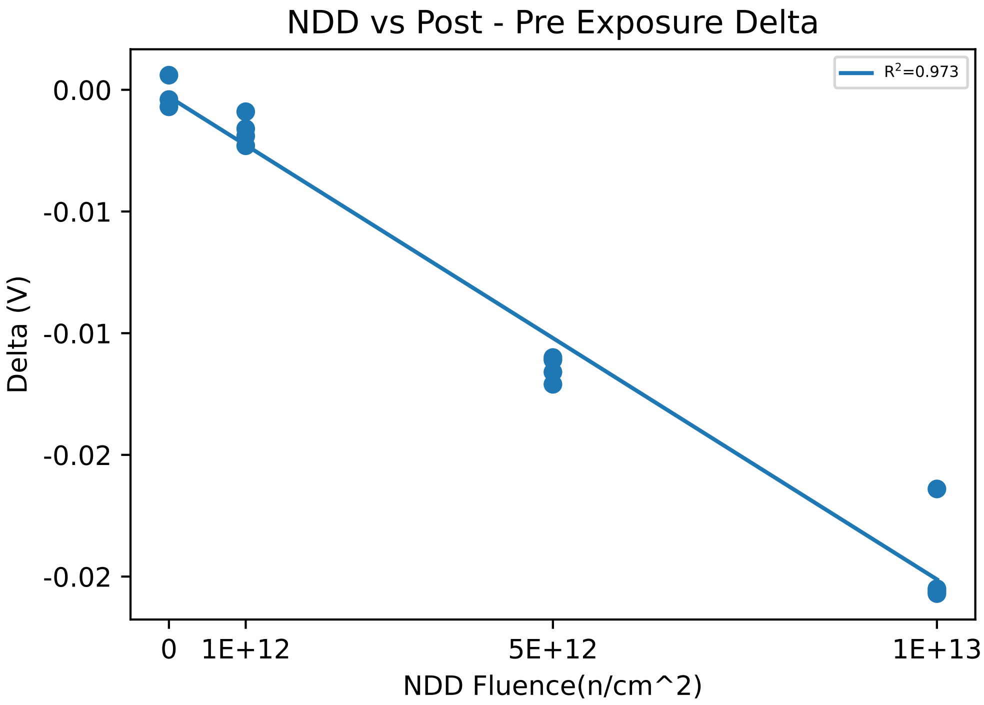
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	237.85	241.1	3.2496
2	1e+12	NDD	238.87	242	3.1366
3	1e+12	NDD	242.06	233.02	-9.0416
4	1e+12	NDD	237.86	241.1	3.2325
5	5e+12	NDD	238.95	241.72	2.7684
6	5e+12	NDD	242.14	233.14	-9.0014
7	5e+12	NDD	237.85	241.15	3.2954
8	5e+12	NDD	238.89	242.09	3.1987
9	1e+13	NDD	242.07	233.08	-8.9952
10	1e+13	NDD	237.71	240.97	3.2575
11	1e+13	NDD	238.94	242	3.0517
12	1e+13	NDD	242.16	233.11	-9.0521
13	0	CORRELATION	237.79	241.17	3.3775
14	0	CORRELATION	238.92	242.14	3.2295
15	0	CORRELATION	242.14	233.01	-9.123

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	237.79	239.61	242.14	2.2561	233.01	238.77	242.14	5.0138	-9.123	-0.83867	3.3775	7.1748
1e+12	237.85	239.16	242.06	1.9927	233.02	239.3	242	4.2109	-9.0416	0.14427	3.2496	6.1241
5e+12	237.85	239.46	242.14	1.8564	233.14	239.52	242.09	4.2755	-9.0014	0.065275	3.2954	6.0488
1e+13	237.71	240.22	242.16	2.2468	233.08	237.29	242	4.86	-9.0521	-2.9345	3.2575	7.0317

Device Test: 15.15 VLDO|V_VLDO/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_5P5





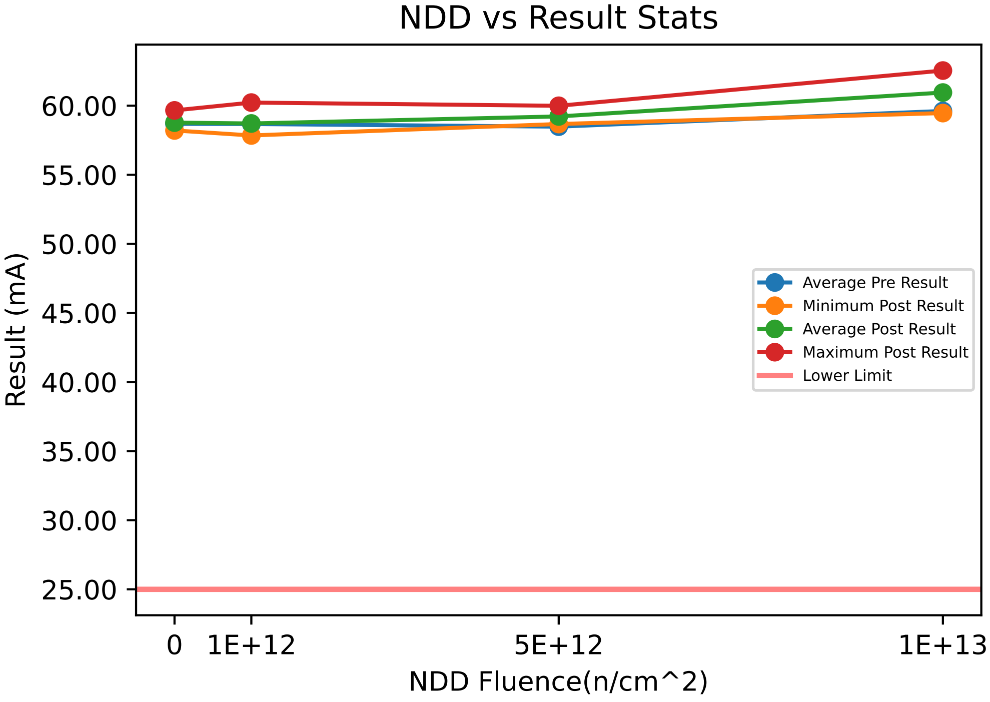
Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

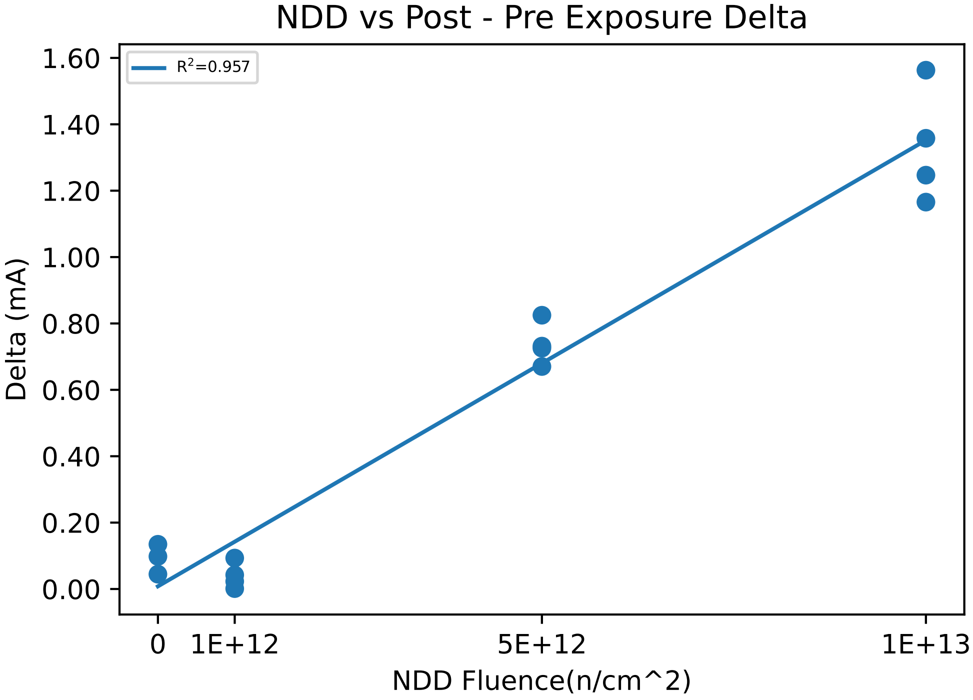
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.4945	5.4926	-0.0019
2	1e+12	NDD	5.4872	5.4863	-0.0009
3	1e+12	NDD	5.495	5.4927	-0.0023
4	1e+12	NDD	5.4955	5.4939	-0.0016
5	5e+12	NDD	5.489	5.4769	-0.0121
6	5e+12	NDD	5.4979	5.4868	-0.0111
7	5e+12	NDD	5.4876	5.4766	-0.011
8	5e+12	NDD	5.482	5.4704	-0.0116
9	1e+13	NDD	5.4738	5.4531	-0.0207
10	1e+13	NDD	5.4821	5.4615	-0.0206
11	1e+13	NDD	5.4874	5.471	-0.0164
12	1e+13	NDD	5.5017	5.4812	-0.0205
13	0	CORRELATION	5.4754	5.475	-0.0004
14	0	CORRELATION	5.4887	5.4893	0.0006
15	0	CORRELATION	5.5006	5.4999	-0.0007

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4754	5.4882	5.5006	0.012606	5.475	5.4881	5.4999	0.012496	-0.0007	-0.00016667	0.0006	0.00068069
1e+12	5.4872	5.4931	5.4955	0.0039213	5.4863	5.4914	5.4939	0.0034345	-0.0023	-0.001675	-0.0009	0.0005909
5e+12	5.482	5.4891	5.4979	0.0065855	5.4704	5.4777	5.4868	0.006781	-0.0121	-0.01145	-0.011	0.00050662
1e+13	5.4738	5.4863	5.5017	0.011722	5.4531	5.4667	5.4812	0.012121	-0.0207	-0.01955	-0.0164	0.0021016

Device Test: 15.16 VLDO|ILIM_VLDO/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_PLUS_0P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

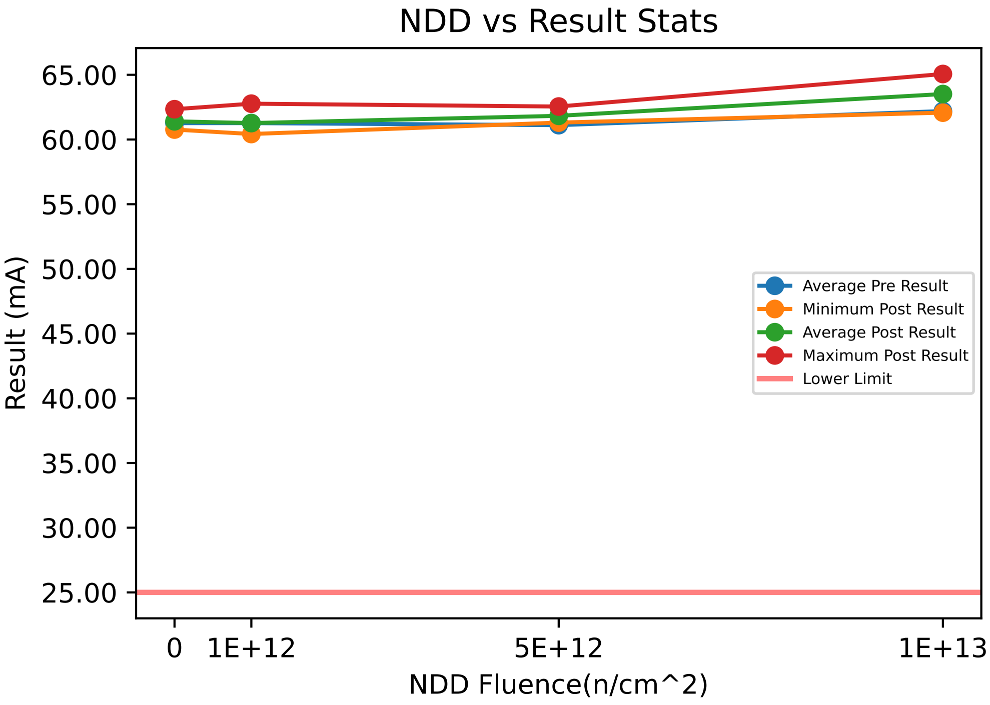
Test Results (Lower Limit = 25.0 (mA))

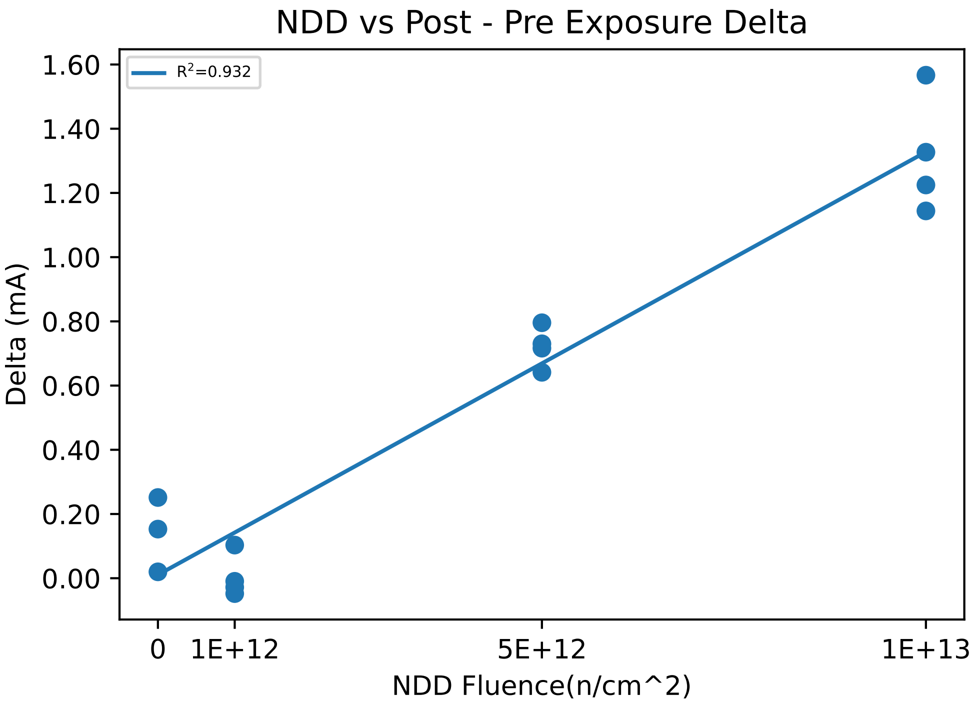
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60.224	60.225	0.0012
2	1e+12	NDD	58.289	58.312	0.0229
3	1e+12	NDD	57.803	57.846	0.0422
4	1e+12	NDD	58.377	58.471	0.0932
5	5e+12	NDD	58.674	59.499	0.8248
6	5e+12	NDD	58.004	58.674	0.6703
7	5e+12	NDD	57.996	58.721	0.7257
8	5e+12	NDD	59.261	59.993	0.7317
9	1e+13	NDD	59.971	61.218	1.2468
10	1e+13	NDD	60.98	62.543	1.563
11	1e+13	NDD	59.414	60.58	1.1656
12	1e+13	NDD	58.108	59.465	1.3579
13	0	CORRELATION	59.524	59.659	0.1347
14	0	CORRELATION	58.364	58.462	0.0981
15	0	CORRELATION	58.163	58.208	0.0446

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	58.163	58.684	59.524	0.73469	58.208	58.776	59.659	0.77487	0.0446	0.092467	0.1347	0.045313
1e+12	57.803	58.673	60.224	1.0638	57.846	58.713	60.225	1.042	0.0012	0.039875	0.0932	0.039297
5e+12	57.996	58.484	59.261	0.60803	58.674	59.222	59.993	0.63815	0.6703	0.73813	0.8248	0.064053
1e+13	58.108	59.618	60.98	1.1977	59.465	60.952	62.543	1.2847	1.1656	1.3333	1.563	0.17221

Device Test: 15.17 VLDO|ILIM_VLDO_SWEEP/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_PLUS_0P5





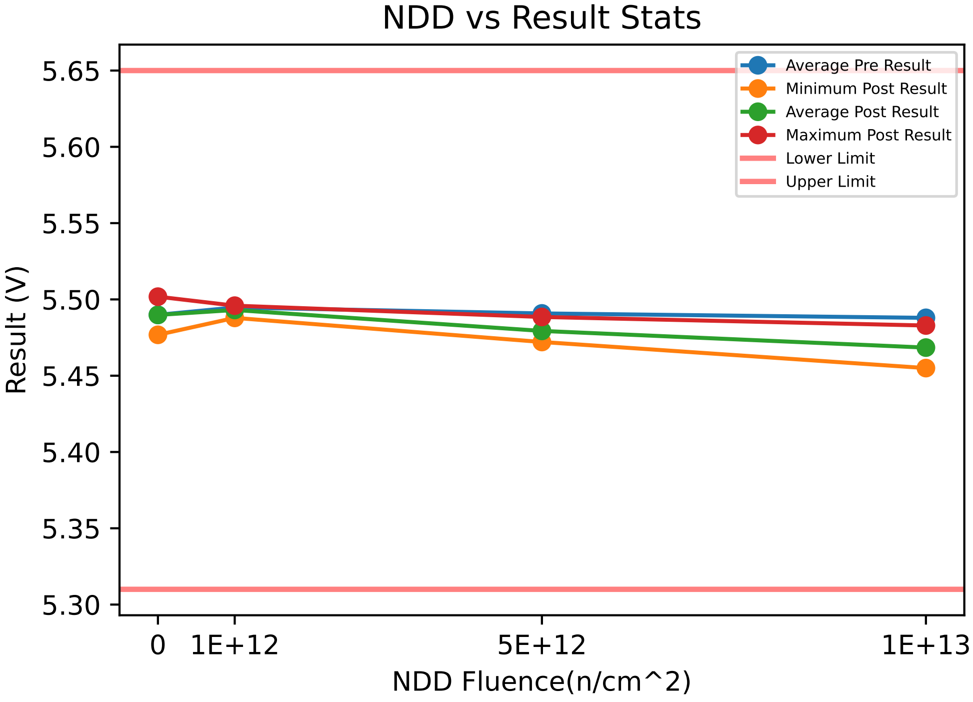
Test Results (Lower Limit = 25.0 (mA))

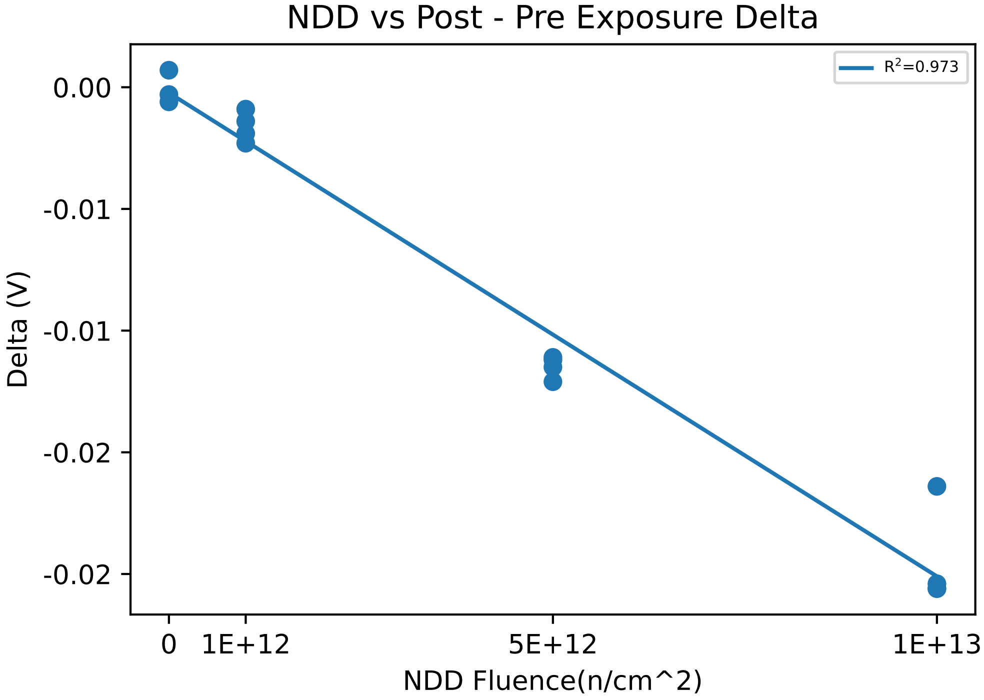
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.816	62.768	-0.0479
2	1e+12	NDD	60.863	60.834	-0.0282
3	1e+12	NDD	60.434	60.425	-0.0096
4	1e+12	NDD	60.95	61.053	0.1032
5	5e+12	NDD	61.33	62.126	0.7957
6	5e+12	NDD	60.665	61.307	0.6413
7	5e+12	NDD	60.608	61.338	0.7301
8	5e+12	NDD	61.832	62.548	0.7165
9	1e+13	NDD	62.535	63.76	1.2248
10	1e+13	NDD	63.496	65.062	1.5667
11	1e+13	NDD	62.013	63.157	1.144
12	1e+13	NDD	60.748	62.075	1.3269
13	0	CORRELATION	62.089	62.34	0.2514
14	0	CORRELATION	60.954	61.107	0.153
15	0	CORRELATION	60.751	60.77	0.0199

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60.751	61.264	62.089	0.72139	60.77	61.406	62.34	0.82672	0.0199	0.14143	0.2514	0.11618
1e+12	60.434	61.266	62.816	1.0579	60.425	61.27	62.768	1.0322	-0.0479	0.004375	0.1032	0.067714
5e+12	60.608	61.109	61.832	0.583	61.307	61.83	62.548	0.61095	0.6413	0.7209	0.7957	0.063338
1e+13	60.748	62.198	63.496	1.1451	62.075	63.514	65.062	1.2458	1.144	1.3156	1.5667	0.18337

Device Test: 15.18 VLDO|V_VLDO/VLDO/12/12/0/0/5.5/500kHz//@V_LDO_5P5





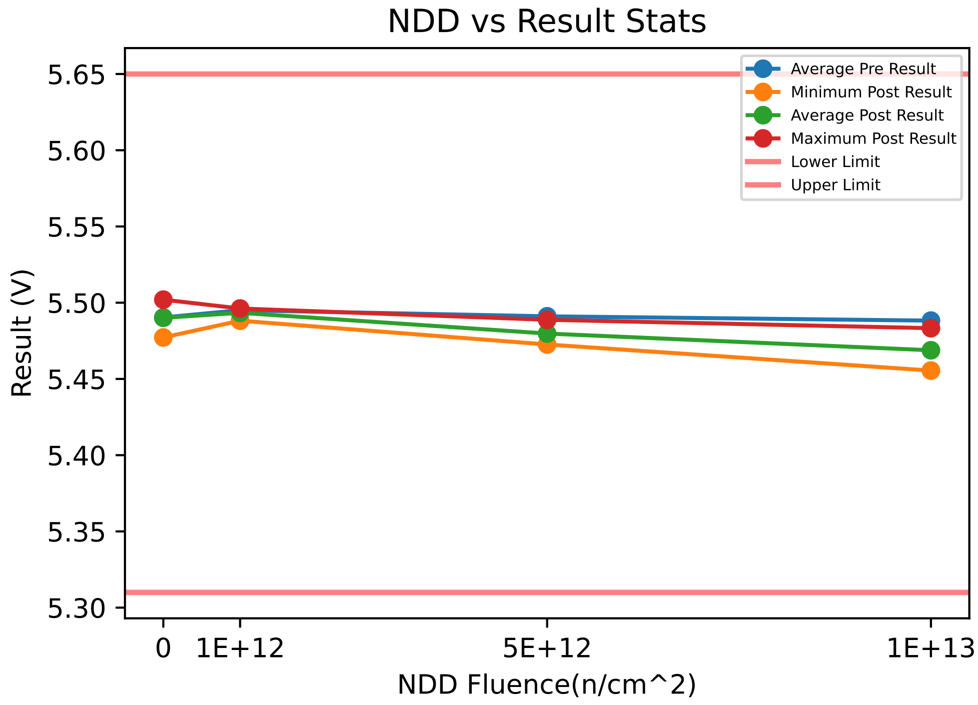
Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

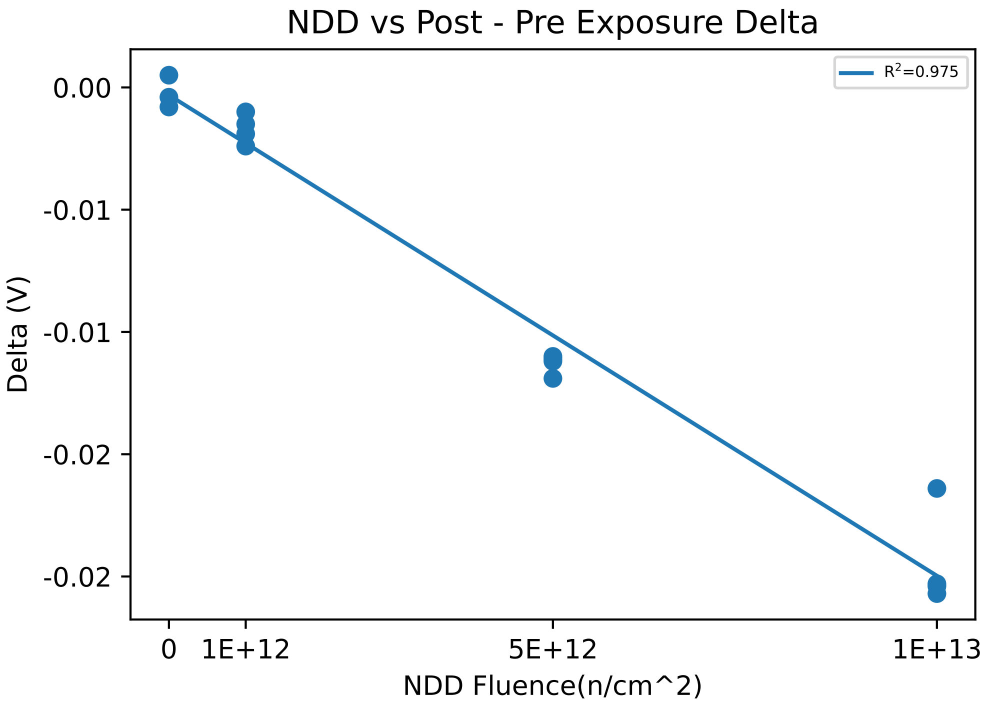
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.4961	5.4942	-0.0019
2	1e+12	NDD	5.4888	5.4879	-0.0009
3	1e+12	NDD	5.4966	5.4943	-0.0023
4	1e+12	NDD	5.4973	5.4959	-0.0014
5	5e+12	NDD	5.4906	5.4785	-0.0121
6	5e+12	NDD	5.4997	5.4885	-0.0112
7	5e+12	NDD	5.4894	5.4783	-0.0111
8	5e+12	NDD	5.4836	5.4721	-0.0115
9	1e+13	NDD	5.4756	5.455	-0.0206
10	1e+13	NDD	5.4837	5.4631	-0.0206
11	1e+13	NDD	5.4891	5.4727	-0.0164
12	1e+13	NDD	5.5033	5.4829	-0.0204
13	0	CORRELATION	5.4771	5.4768	-0.0003
14	0	CORRELATION	5.4902	5.4909	0.0007
15	0	CORRELATION	5.5024	5.5018	-0.0006

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4771	5.4899	5.5024	0.012653	5.4768	5.4898	5.5018	0.012534	-0.0006	-6.6667e-05	0.0007	0.00068069
1e+12	5.4888	5.4947	5.4973	0.003964	5.4879	5.4931	5.4959	0.0035368	-0.0023	-0.001625	-0.0009	0.00060759
5e+12	5.4836	5.4908	5.4997	0.0066595	5.4721	5.4794	5.4885	0.006785	-0.0121	-0.011475	-0.0111	0.00045
1e+13	5.4756	5.4879	5.5033	0.011655	5.455	5.4684	5.4829	0.012061	-0.0206	-0.0195	-0.0164	0.0020688

Device Test: 15.19 VLDO|V_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_5P5





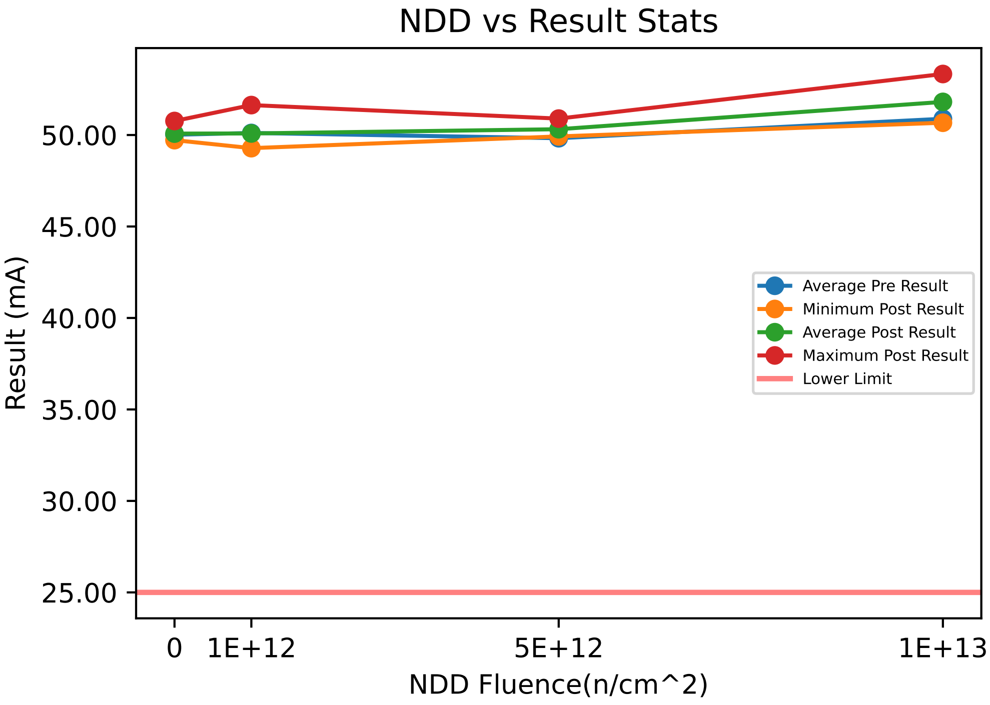
Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.4964	5.4945	-0.0019
2	1e+12	NDD	5.4892	5.4882	-0.001
3	1e+12	NDD	5.497	5.4946	-0.0024
4	1e+12	NDD	5.4977	5.4962	-0.0015
5	5e+12	NDD	5.4909	5.479	-0.0119
6	5e+12	NDD	5.4999	5.4888	-0.0111
7	5e+12	NDD	5.4897	5.4787	-0.011
8	5e+12	NDD	5.4838	5.4726	-0.0112
9	1e+13	NDD	5.4758	5.4555	-0.0203
10	1e+13	NDD	5.484	5.4633	-0.0207
11	1e+13	NDD	5.4895	5.4731	-0.0164
12	1e+13	NDD	5.5037	5.4833	-0.0204
13	0	CORRELATION	5.4776	5.4772	-0.0004
14	0	CORRELATION	5.4906	5.4911	0.0005
15	0	CORRELATION	5.5028	5.502	-0.0008

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4776	5.4903	5.5028	0.012602	5.4772	5.4901	5.502	0.01243	-0.0008	-0.00023333	0.0005	0.00066583
1e+12	5.4892	5.4951	5.4977	0.0039525	5.4882	5.4934	5.4962	0.0035368	-0.0024	-0.0017	-0.001	0.00059442
5e+12	5.4838	5.4911	5.4999	0.0066515	5.4726	5.4798	5.4888	0.0067004	-0.0119	-0.0113	-0.011	0.00040825
1e+13	5.4758	5.4882	5.5037	0.011738	5.4555	5.4688	5.4833	0.012054	-0.0207	-0.01945	-0.0164	0.0020404

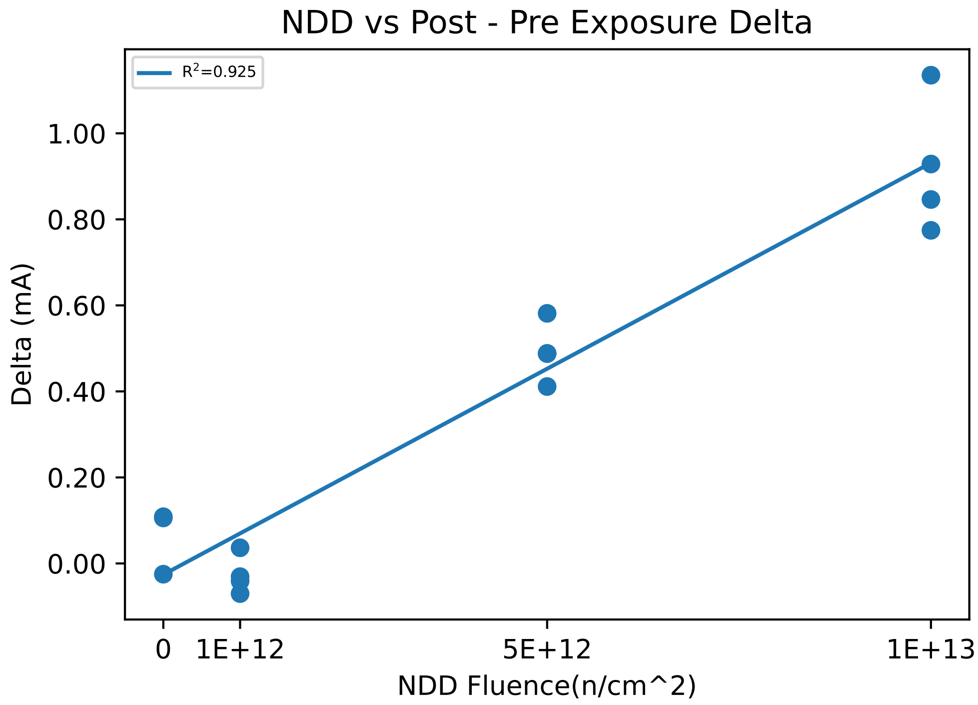
Device Test: 15.2 VLDO|ILIM_VLDO/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_PLUS_0P5



NDD vs Result Stats

Test Results (Lower Limit = 25.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	51.667	51.636	-0.0307
2	1e+12	NDD	49.555	49.514	-0.0411
3	1e+12	NDD	49.352	49.282	-0.0701
4	1e+12	NDD	49.874	49.91	0.0364
5	5e+12	NDD	49.893	50.474	0.5814
6	5e+12	NDD	49.562	49.974	0.4113
7	5e+12	NDD	49.435	49.923	0.4879
8	5e+12	NDD	50.409	50.897	0.4883
9	1e+13	NDD	51.002	51.777	0.7744
10	1e+13	NDD	52.2	53.335	1.1351
11	1e+13	NDD	50.611	51.457	0.8461
12	1e+13	NDD	49.743	50.671	0.9286
13	0	CORRELATION	50.657	50.766	0.1086
14	0	CORRELATION	49.641	49.747	0.1058
15	0	CORRELATION	49.745	49.72	-0.025

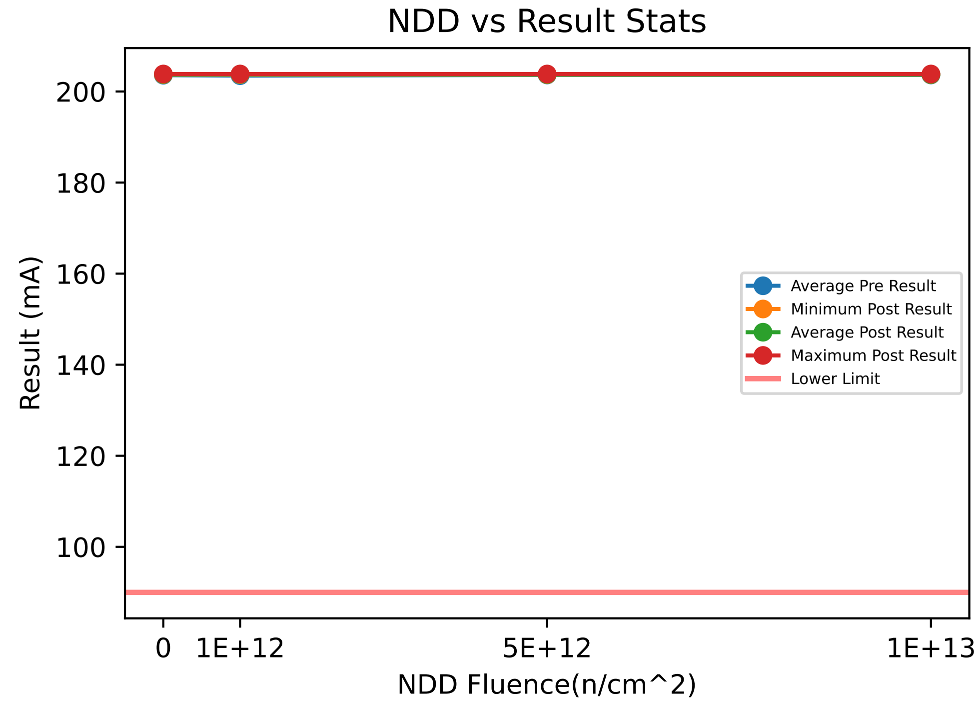


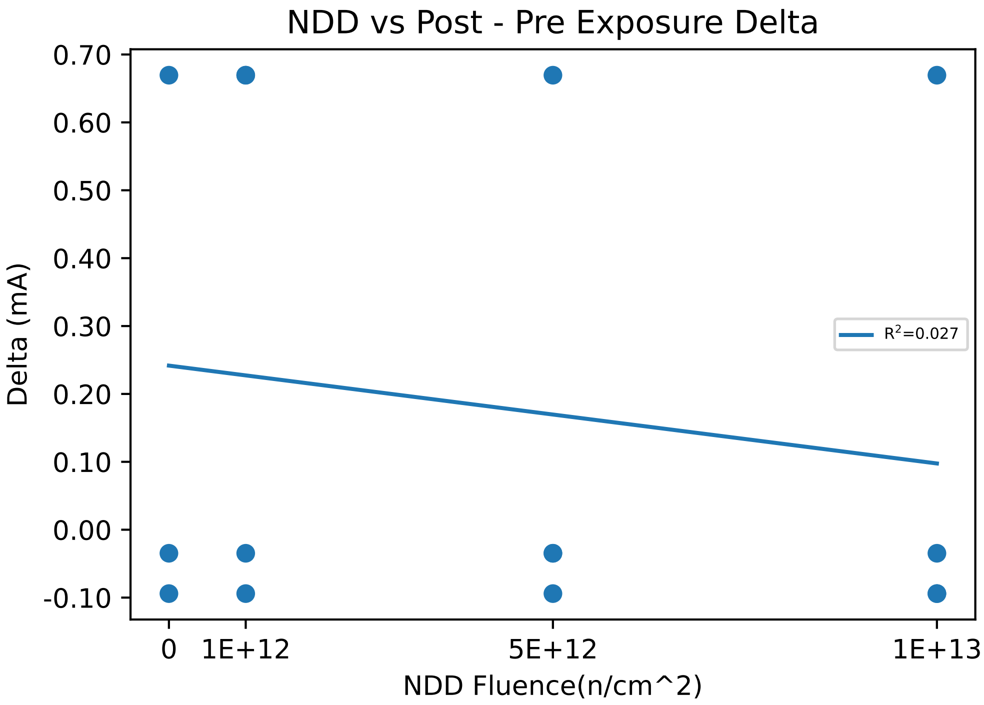
NDD vs Post - Pre Exposure Delta

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.641	50.014	50.657	0.55893	49.72	50.078	50.766	0.59607	-0.025	0.063133	0.1086	0.076339
1e+12	49.352	50.112	51.667	1.0584	49.282	50.086	51.636	1.0656	-0.0701	-0.026375	0.0364	0.045049
5e+12	49.435	49.825	50.409	0.43454	49.923	50.317	50.897	0.45984	0.4113	0.49223	0.5814	0.069606
1e+13	49.743	50.889	52.2	1.0203	50.671	51.81	53.335	1.1178	0.7744	0.92105	1.1351	0.15599

Device Test: 15.20 VLDO|ILIM_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_7





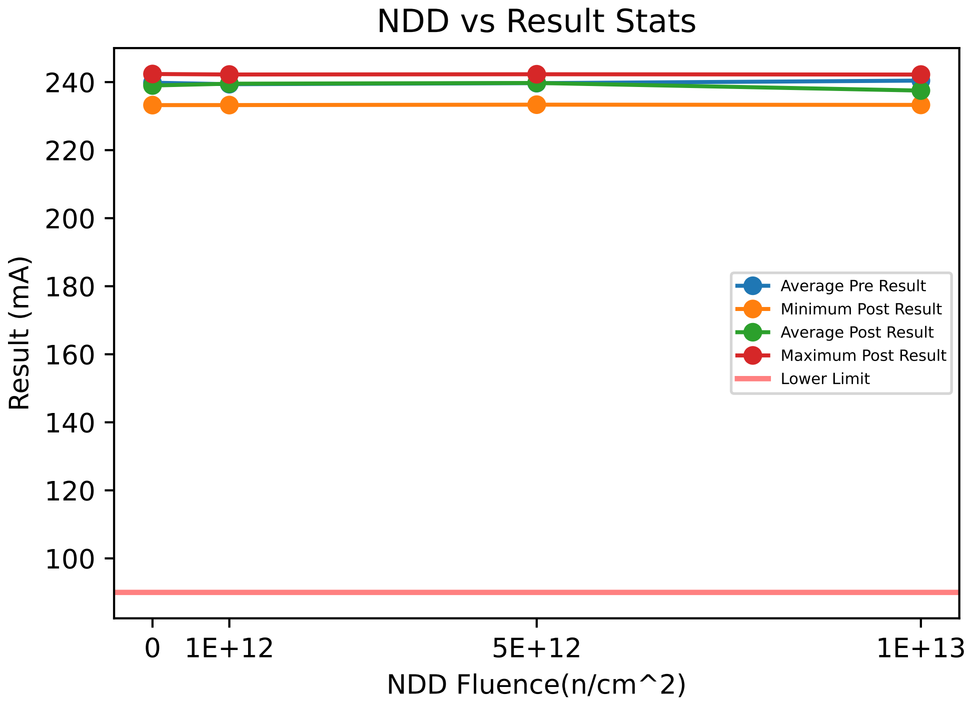
Test Results (Lower Limit = 90.0 (mA))

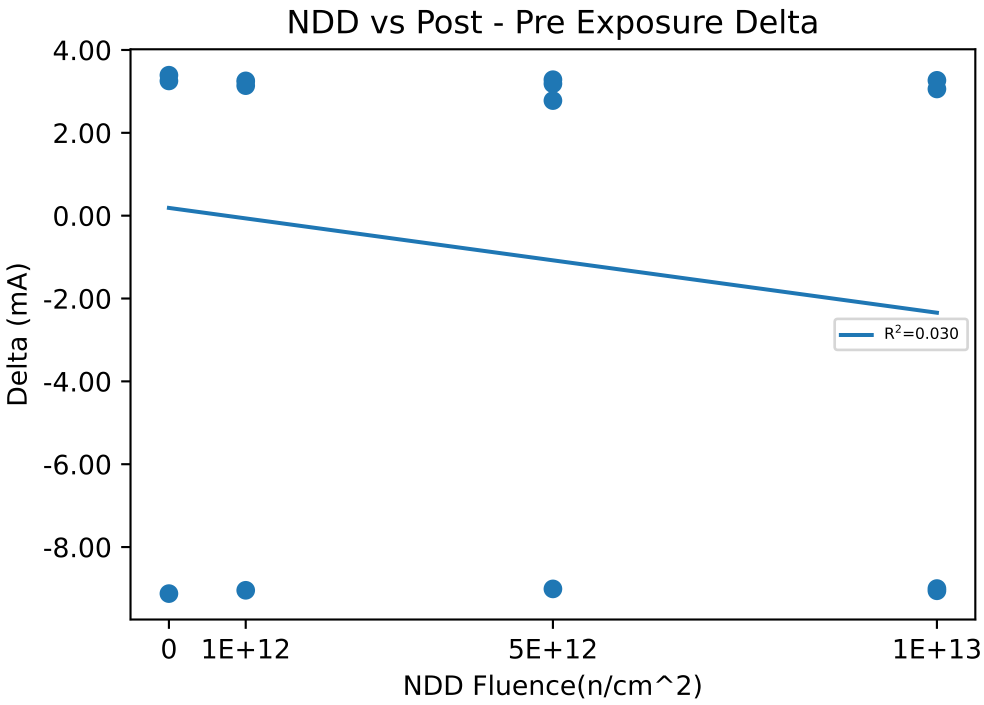
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	203.18	203.84	0.6695
2	1e+12	NDD	203.78	203.75	-0.0347
3	1e+12	NDD	203.79	203.69	-0.0941
4	1e+12	NDD	203.18	203.84	0.6695
5	5e+12	NDD	203.78	203.75	-0.0347
6	5e+12	NDD	203.79	203.69	-0.0941
7	5e+12	NDD	203.18	203.84	0.6695
8	5e+12	NDD	203.78	203.75	-0.0347
9	1e+13	NDD	203.79	203.69	-0.0941
10	1e+13	NDD	203.18	203.84	0.6695
11	1e+13	NDD	203.78	203.75	-0.0347
12	1e+13	NDD	203.79	203.69	-0.0941
13	0	CORRELATION	203.18	203.84	0.6695
14	0	CORRELATION	203.78	203.75	-0.0347
15	0	CORRELATION	203.79	203.69	-0.0941

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	203.18	203.58	203.79	0.35164	203.69	203.76	203.84	0.077132	-0.0941	0.18023	0.6695	0.42476
1e+12	203.18	203.48	203.79	0.35164	203.69	203.78	203.84	0.075486	-0.0941	0.30255	0.6695	0.42441
5e+12	203.18	203.63	203.79	0.30416	203.69	203.76	203.84	0.063375	-0.0941	0.1265	0.6695	0.36308
1e+13	203.18	203.63	203.79	0.30491	203.69	203.74	203.84	0.071825	-0.0941	0.11165	0.6695	0.37295

Device Test: 15.21 VLDO|ILIM_VLDO_SWEEP/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_7





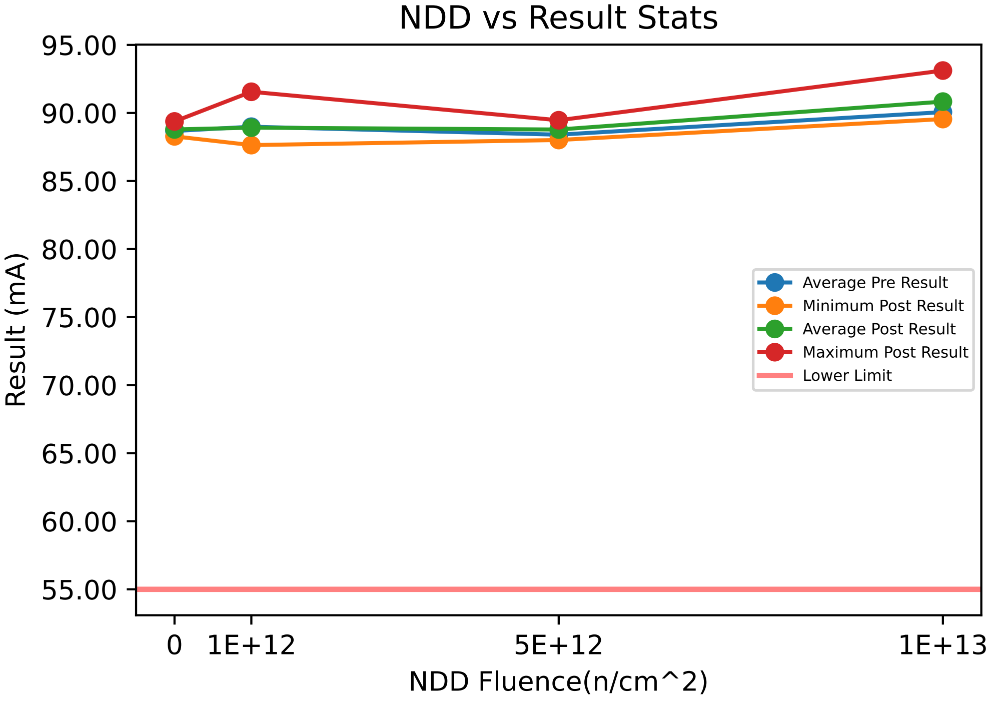
Test Results (Lower Limit = 90.0 (mA))

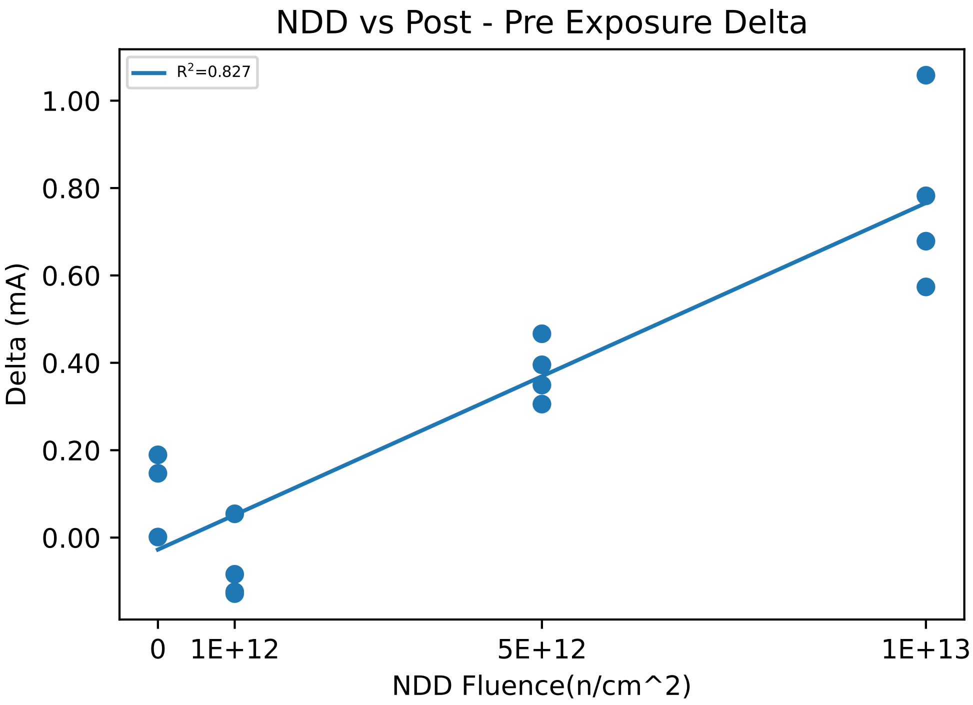
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	238.06	241.32	3.254
2	1e+12	NDD	239.1	242.23	3.1388
3	1e+12	NDD	242.29	233.25	-9.0437
4	1e+12	NDD	238.08	241.32	3.2409
5	5e+12	NDD	239.18	241.96	2.7781
6	5e+12	NDD	242.38	233.37	-9.0102
7	5e+12	NDD	238.07	241.36	3.2826
8	5e+12	NDD	239.12	242.31	3.1854
9	1e+13	NDD	242.3	233.3	-9.0016
10	1e+13	NDD	237.91	241.18	3.2672
11	1e+13	NDD	239.16	242.22	3.0588
12	1e+13	NDD	242.39	233.33	-9.0554
13	0	CORRELATION	238	241.39	3.3911
14	0	CORRELATION	239.13	242.38	3.2525
15	0	CORRELATION	242.36	233.24	-9.1235

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	238	239.83	242.36	2.2637	233.24	239	242.38	5.0178	-9.1235	-0.82663	3.3911	7.1856
1e+12	238.06	239.38	242.29	1.9984	233.25	239.53	242.23	4.2105	-9.0437	0.1475	3.254	6.1277
5e+12	238.07	239.69	242.38	1.8637	233.37	239.75	242.31	4.2714	-9.0102	0.058975	3.2826	6.0501
1e+13	237.91	240.44	242.39	2.2566	233.3	237.51	242.22	4.8591	-9.0554	-2.9328	3.2672	7.0393

Device Test: 15.28 VLDO|ILIM_VLDO/VLDO/5.5/5.5/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_PLUS_1


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

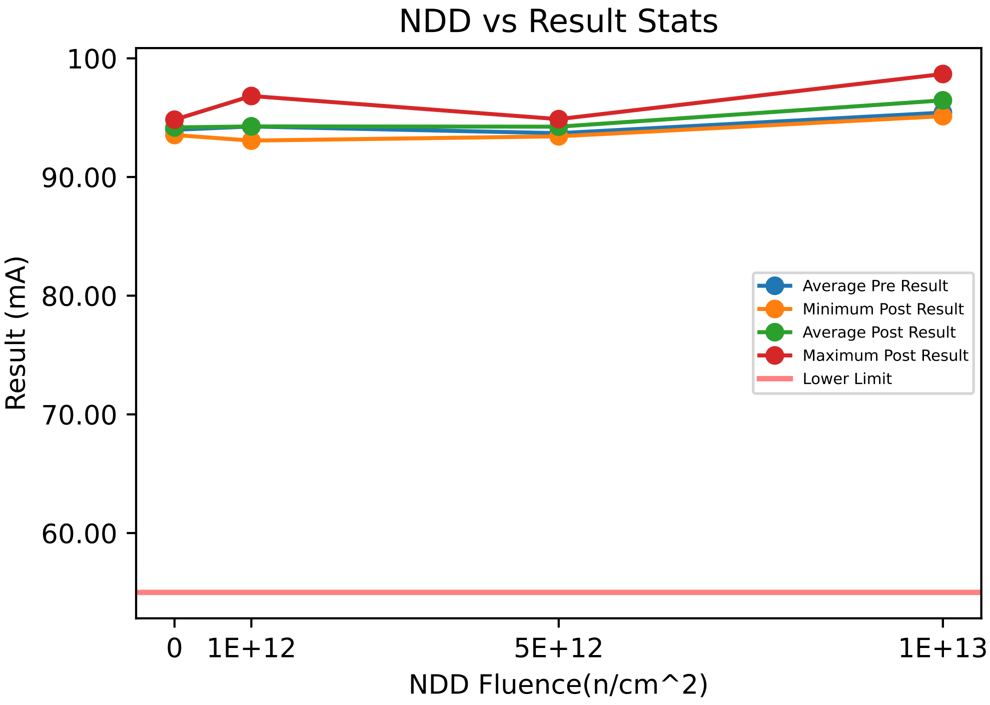
Test Results (Lower Limit = 55.0 (mA))

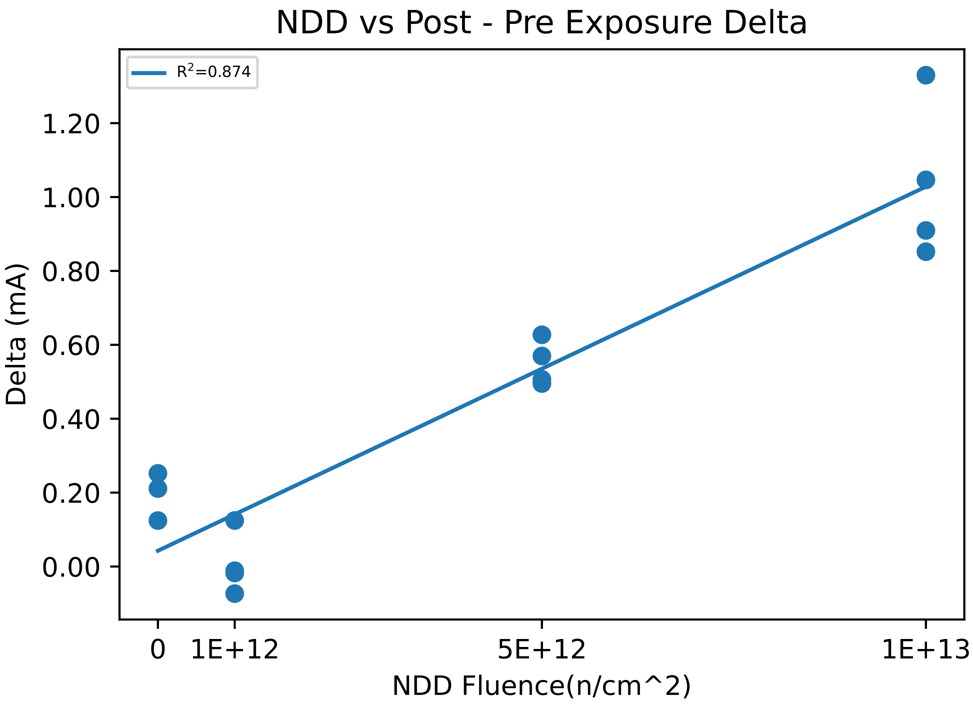
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	91.682	91.558	-0.1241
2	1e+12	NDD	87.845	87.761	-0.084
3	1e+12	NDD	87.768	87.64	-0.1282
4	1e+12	NDD	88.669	88.723	0.0544
5	5e+12	NDD	88.59	89.057	0.4665
6	5e+12	NDD	88.298	88.603	0.3055
7	5e+12	NDD	87.618	88.013	0.3955
8	5e+12	NDD	89.116	89.466	0.3491
9	1e+13	NDD	89.676	90.249	0.5737
10	1e+13	NDD	92.059	93.118	1.0583
11	1e+13	NDD	89.742	90.421	0.6784
12	1e+13	NDD	88.772	89.554	0.7822
13	0	CORRELATION	89.188	89.378	0.1894
14	0	CORRELATION	88.134	88.281	0.1471
15	0	CORRELATION	88.713	88.714	0.0013

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	88.134	88.678	89.188	0.52795	88.281	88.791	89.378	0.55227	0.0013	0.1126	0.1894	0.098682
1e+12	87.768	88.991	91.682	1.8396	87.64	88.92	91.558	1.8237	-0.1282	-0.070475	0.0544	0.085605
5e+12	87.618	88.406	89.116	0.62483	88.013	88.785	89.466	0.6232	0.3055	0.37915	0.4665	0.068859
1e+13	88.772	90.062	92.059	1.4029	89.554	90.835	93.118	1.5669	0.5737	0.77315	1.0583	0.20829

Device Test: 15.29 VLDO|ILIM_VLDO/VLDO/6/6/0/0/5/500kHz//@V_LDO_ILIM_5_PLUS_1





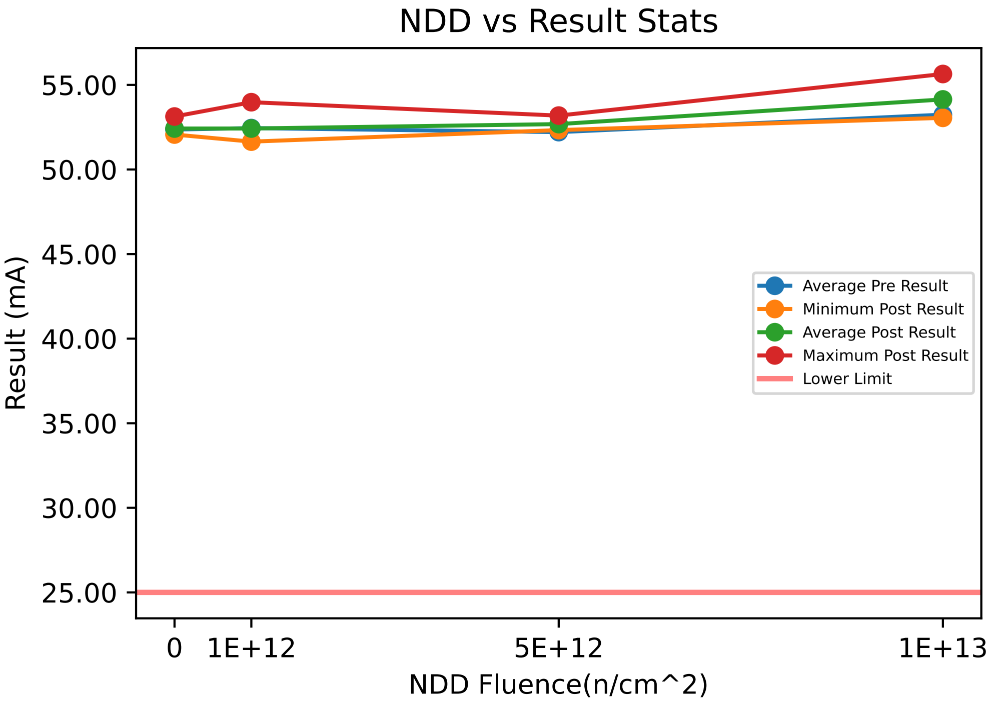
Test Results (Lower Limit = 55.0 (mA))

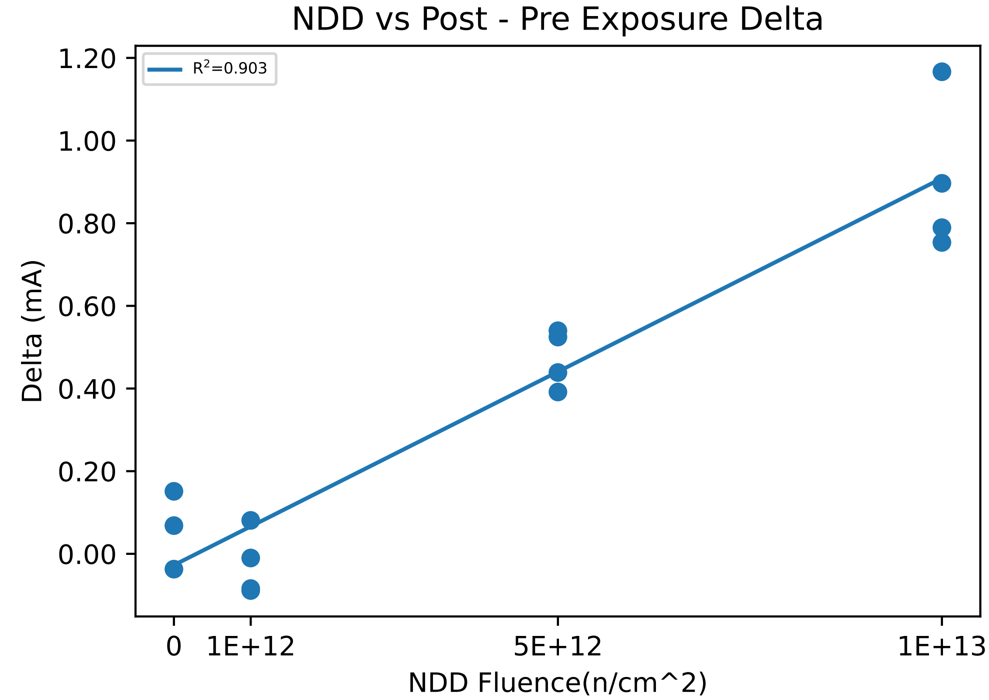
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	96.9	96.827	-0.0733
2	1e+12	NDD	93.08	93.068	-0.0114
3	1e+12	NDD	93.148	93.131	-0.0175
4	1e+12	NDD	93.905	94.03	0.1245
5	5e+12	NDD	93.869	94.496	0.6272
6	5e+12	NDD	93.657	94.164	0.5066
7	5e+12	NDD	92.858	93.427	0.5698
8	5e+12	NDD	94.382	94.877	0.4953
9	1e+13	NDD	95.312	96.165	0.8521
10	1e+13	NDD	97.35	98.68	1.3298
11	1e+13	NDD	94.956	95.866	0.9096
12	1e+13	NDD	94.082	95.128	1.0464
13	0	CORRELATION	94.576	94.829	0.2521
14	0	CORRELATION	93.328	93.539	0.211
15	0	CORRELATION	94.032	94.156	0.1244

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	93.328	93.979	94.576	0.626	93.539	94.175	94.829	0.64504	0.1244	0.19583	0.2521	0.065187
1e+12	93.08	94.258	96.9	1.8005	93.068	94.264	96.827	1.7641	-0.0733	0.005575	0.1245	0.084034
5e+12	92.858	93.691	94.382	0.63378	93.427	94.241	94.877	0.61591	0.4953	0.54973	0.6272	0.061175
1e+13	94.082	95.425	97.35	1.3835	95.128	96.46	98.68	1.5429	0.8521	1.0345	1.3298	0.21308

Device Test: 15.3 VLDO|ILIM_VLDO_SWEEP/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_PLUS_0P5





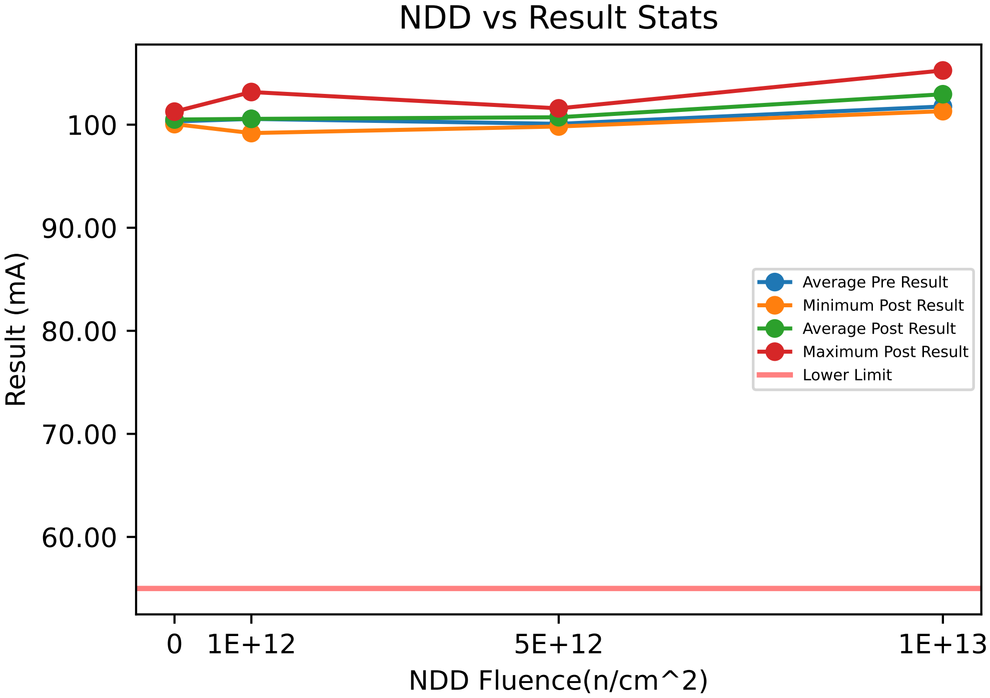
Test Results (Lower Limit = 25.0 (mA))

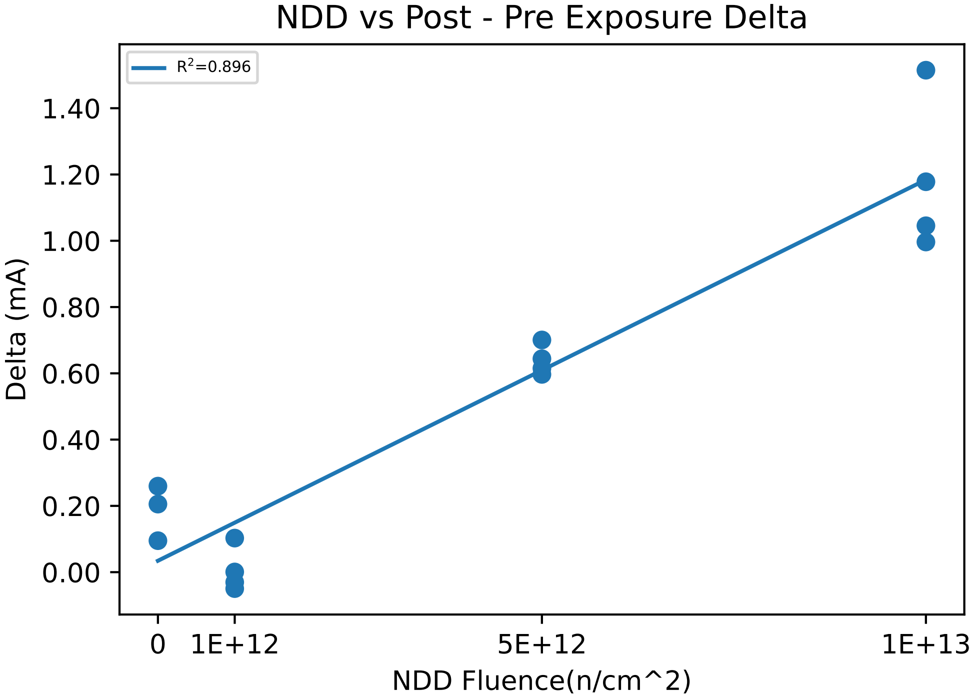
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	53.987	53.977	-0.0101
2	1e+12	NDD	51.87	51.781	-0.0888
3	1e+12	NDD	51.731	51.647	-0.0841
4	1e+12	NDD	52.202	52.283	0.0809
5	5e+12	NDD	52.297	52.837	0.5398
6	5e+12	NDD	51.99	52.382	0.3916
7	5e+12	NDD	51.804	52.328	0.5246
8	5e+12	NDD	52.747	53.186	0.4387
9	1e+13	NDD	53.343	54.097	0.7535
10	1e+13	NDD	54.478	55.645	1.1665
11	1e+13	NDD	52.982	53.772	0.7892
12	1e+13	NDD	52.157	53.053	0.8965
13	0	CORRELATION	52.98	53.131	0.1512
14	0	CORRELATION	52.001	52.069	0.0683
15	0	CORRELATION	52.103	52.066	-0.0371

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.001	52.361	52.98	0.53809	52.066	52.422	53.131	0.61396	-0.0371	0.0608	0.1512	0.094374
1e+12	51.731	52.448	53.987	1.0454	51.647	52.422	53.977	1.0724	-0.0888	-0.025525	0.0809	0.07958
5e+12	51.804	52.209	52.747	0.41217	52.328	52.683	53.186	0.40546	0.3916	0.47367	0.5398	0.070535
1e+13	52.157	53.24	54.478	0.96331	53.053	54.142	55.645	1.0929	0.7535	0.90142	1.1665	0.18687

Device Test: 15.30 VLDO|ILIM_VLDO/VLDO/6.5/6.5/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_PLUS_1


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

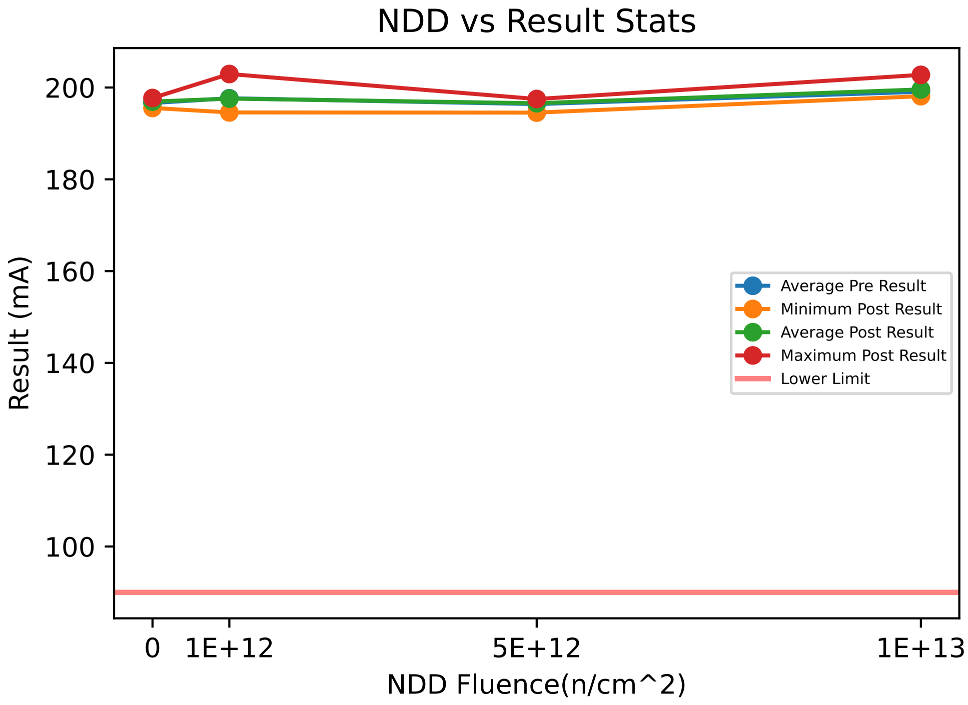
Test Results (Lower Limit = 55.0 (mA))

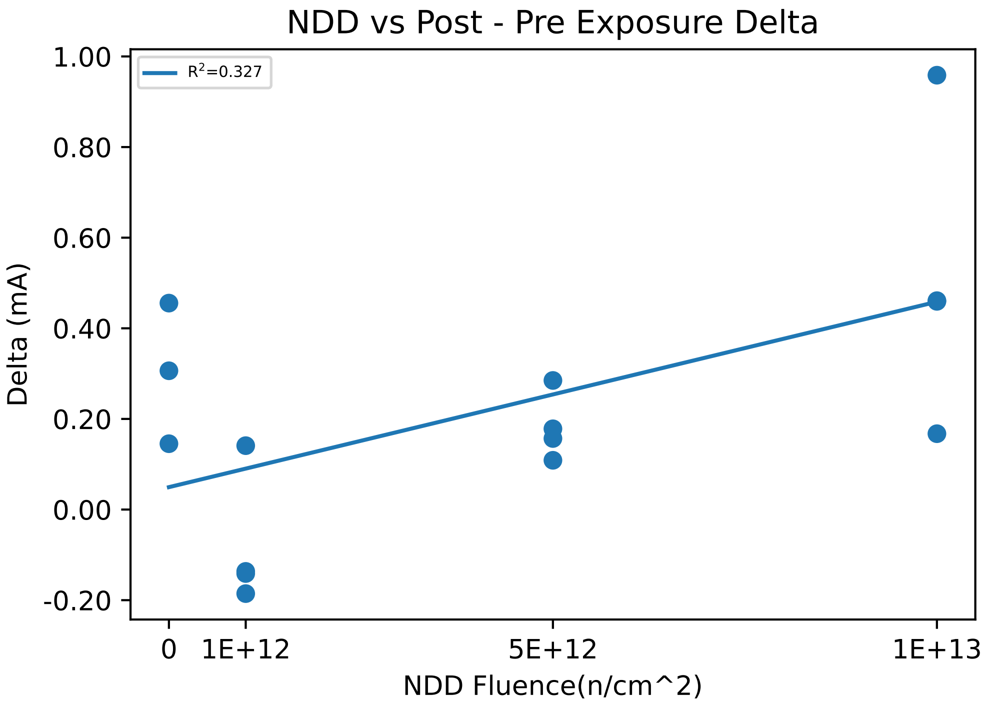
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	103.22	103.17	-0.0496
2	1e+12	NDD	99.609	99.61	0.0006
3	1e+12	NDD	99.216	99.185	-0.0305
4	1e+12	NDD	100.19	100.29	0.1028
5	5e+12	NDD	100.46	101.16	0.7007
6	5e+12	NDD	99.721	100.32	0.5968
7	5e+12	NDD	99.179	99.823	0.644
8	5e+12	NDD	100.97	101.58	0.615
9	1e+13	NDD	101.66	102.66	0.9963
10	1e+13	NDD	103.75	105.26	1.5147
11	1e+13	NDD	101.54	102.58	1.0453
12	1e+13	NDD	100.13	101.31	1.1781
13	0	CORRELATION	101.01	101.26	0.2596
14	0	CORRELATION	99.849	100.05	0.2054
15	0	CORRELATION	100.08	100.18	0.095

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.849	100.31	101.01	0.61119	100.05	100.5	101.26	0.6659	0.095	0.18667	0.2596	0.083884
1e+12	99.216	100.56	103.22	1.8179	99.185	100.56	103.17	1.7952	-0.0496	0.005825	0.1028	0.06788
5e+12	99.179	100.08	100.97	0.79029	99.823	100.72	101.58	0.79697	0.5968	0.63912	0.7007	0.045419
1e+13	100.13	101.77	103.75	1.4896	101.31	102.95	105.26	1.6586	0.9963	1.1836	1.5147	0.23371

Device Test: 15.31 VLDO|ILIM_VLDO/VLDO/7/7/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_7





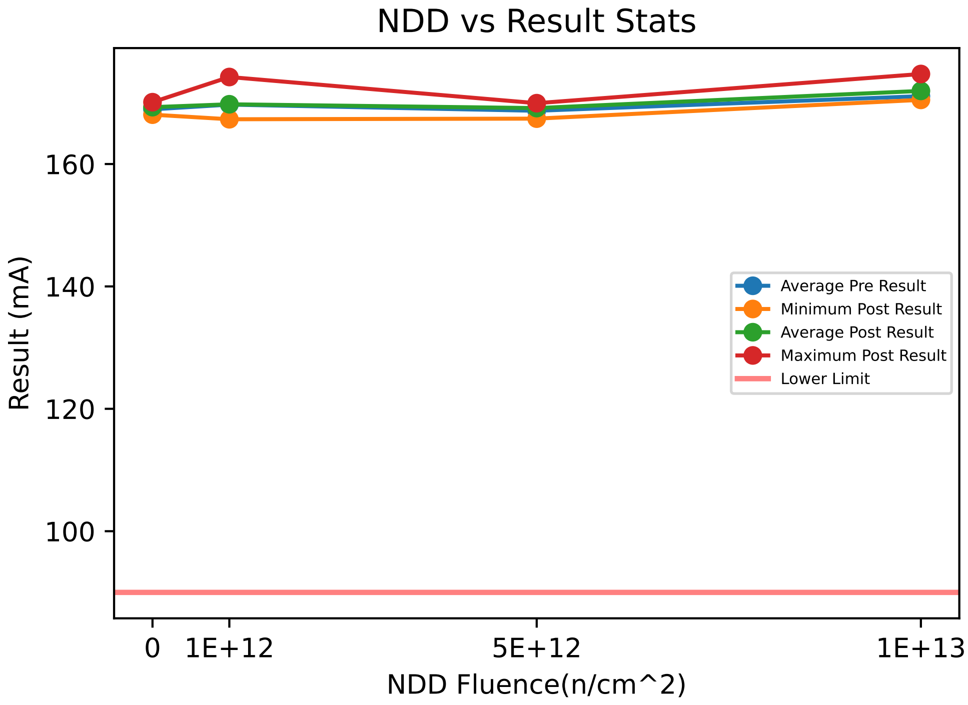
Test Results (Lower Limit = 90.0 (mA))

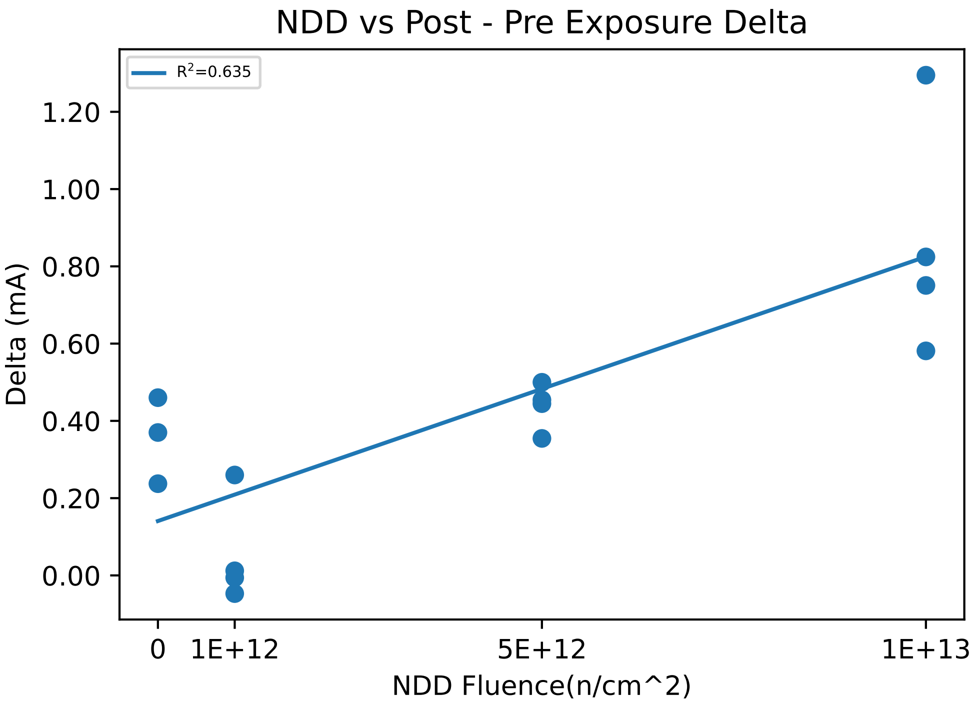
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	203.09	202.95	-0.1412
2	1e+12	NDD	195.1	194.96	-0.1365
3	1e+12	NDD	194.76	194.57	-0.1855
4	1e+12	NDD	197.71	197.85	0.141
5	5e+12	NDD	197.01	197.17	0.1568
6	5e+12	NDD	196.92	197.1	0.1782
7	5e+12	NDD	194.25	194.53	0.2849
8	5e+12	NDD	197.39	197.5	0.1087
9	1e+13	NDD	198.55	198.72	0.1674
10	1e+13	NDD	201.8	202.76	0.9586
11	1e+13	NDD	198.29	198.75	0.4595
12	1e+13	NDD	197.65	198.11	0.461
13	0	CORRELATION	197.25	197.71	0.4556
14	0	CORRELATION	195.24	195.54	0.3063
15	0	CORRELATION	197.39	197.54	0.1453

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	195.24	196.63	197.39	1.2058	195.54	196.93	197.71	1.2035	0.1453	0.3024	0.4556	0.15519
1e+12	194.76	197.66	203.09	3.8484	194.57	197.58	202.95	3.8625	-0.1855	-0.08055	0.141	0.14934
5e+12	194.25	196.39	197.39	1.4425	194.53	196.57	197.5	1.3708	0.1087	0.18215	0.2849	0.07441
1e+13	197.65	199.07	201.8	1.857	198.11	199.58	202.76	2.1363	0.1674	0.51162	0.9586	0.32841

Device Test: 15.32 VLDO|ILIM_VLDO/VLDO/7/7/0/0/5/500kHz//@V_LDO_ILIM_5_7





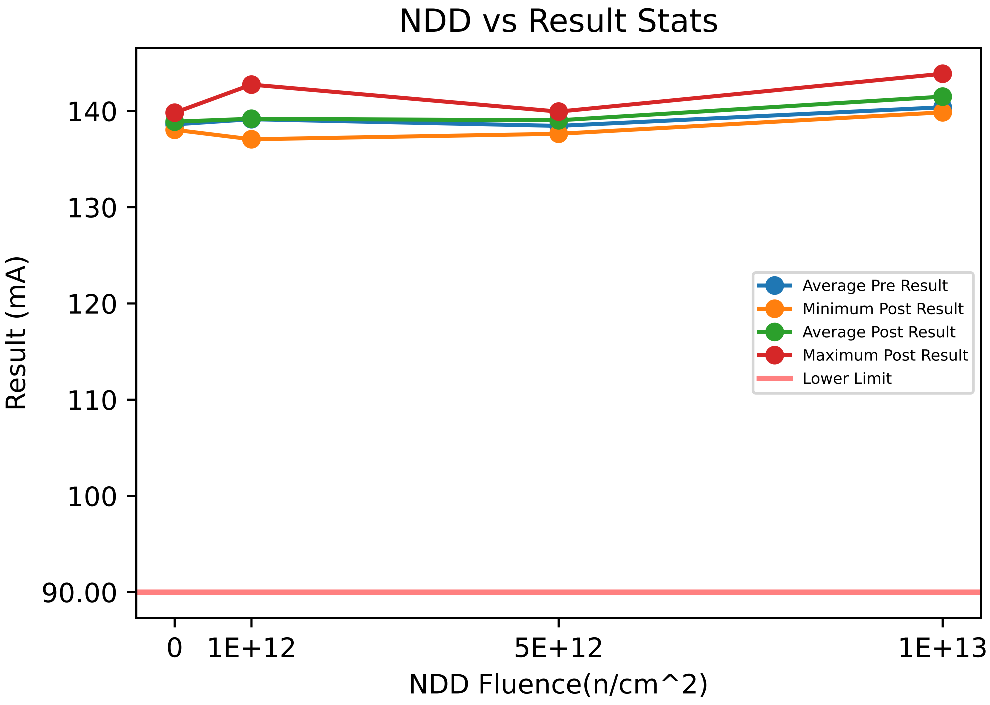
Test Results (Lower Limit = 90.0 (mA))

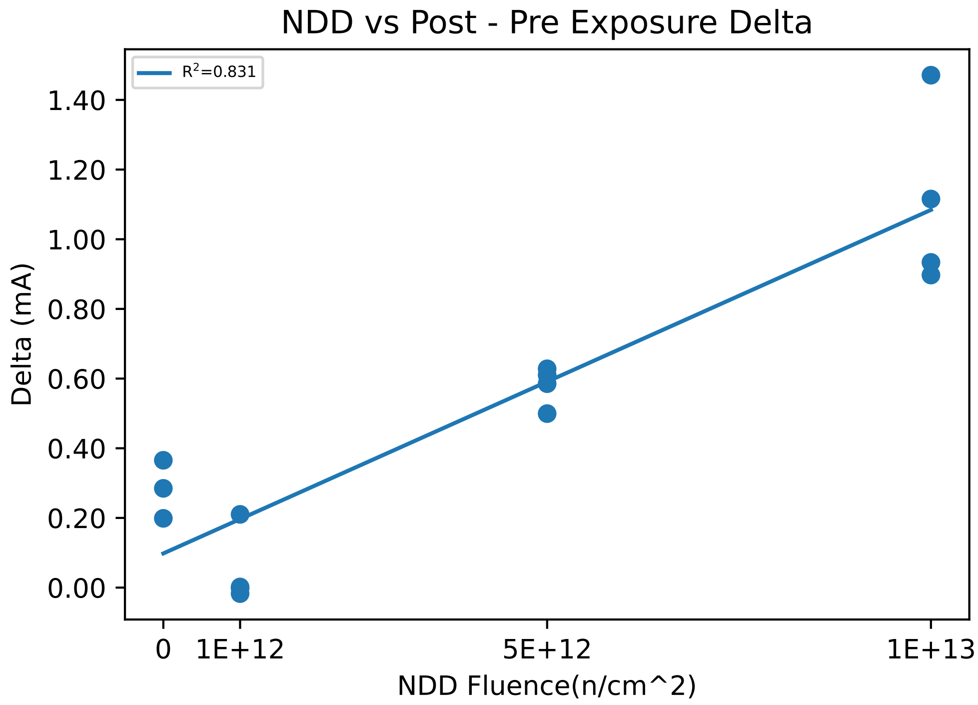
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	174.23	174.22	-0.0059
2	1e+12	NDD	167.58	167.59	0.0119
3	1e+12	NDD	167.36	167.32	-0.0471
4	1e+12	NDD	169.67	169.93	0.2599
5	5e+12	NDD	169.21	169.66	0.4446
6	5e+12	NDD	169.1	169.55	0.4542
7	5e+12	NDD	166.92	167.42	0.4999
8	5e+12	NDD	169.59	169.94	0.3546
9	1e+13	NDD	170.95	171.53	0.5812
10	1e+13	NDD	173.42	174.71	1.2948
11	1e+13	NDD	170.31	171.06	0.7506
12	1e+13	NDD	169.66	170.48	0.8244
13	0	CORRELATION	169.64	170.1	0.4601
14	0	CORRELATION	167.7	168.07	0.3699
15	0	CORRELATION	169.47	169.71	0.2374

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	167.7	168.94	169.64	1.0778	168.07	169.29	170.1	1.0803	0.2374	0.3558	0.4601	0.11202
1e+12	167.36	169.71	174.23	3.1853	167.32	169.76	174.22	3.1934	-0.0471	0.0547	0.2599	0.13901
5e+12	166.92	168.7	169.59	1.2077	167.42	169.14	169.94	1.1602	0.3546	0.43832	0.4999	0.060808
1e+13	169.66	171.08	173.42	1.6422	170.48	171.95	174.71	1.8923	0.5812	0.86275	1.2948	0.3055

Device Test: 15.33 VLDO|ILIM_VLDO/VLDO/7/7/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_7





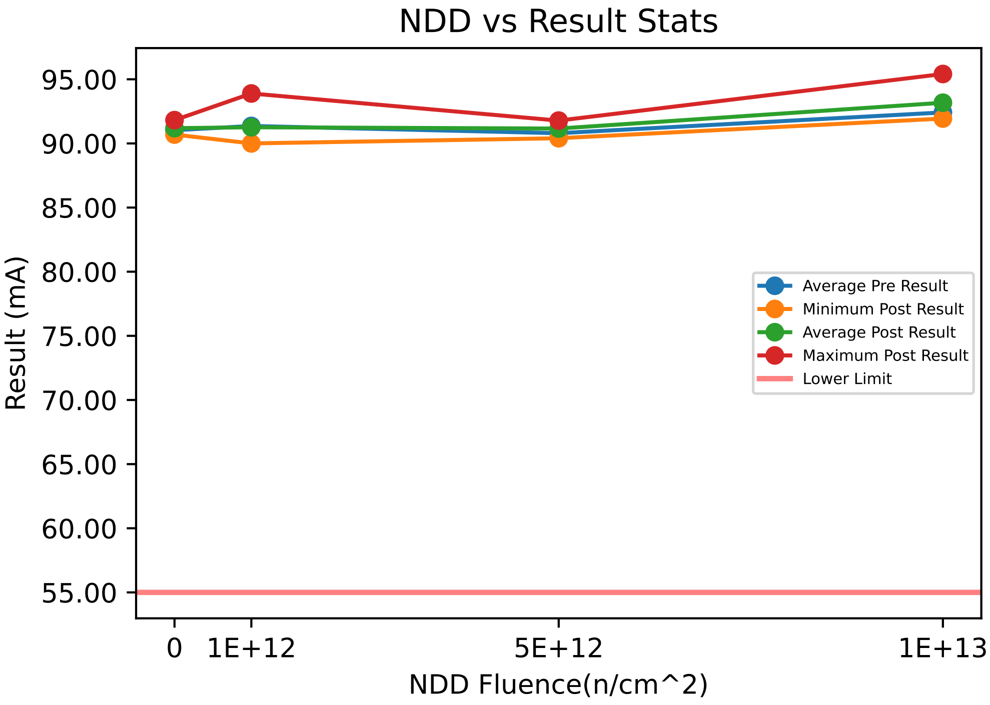
Test Results (Lower Limit = 90.0 (mA))

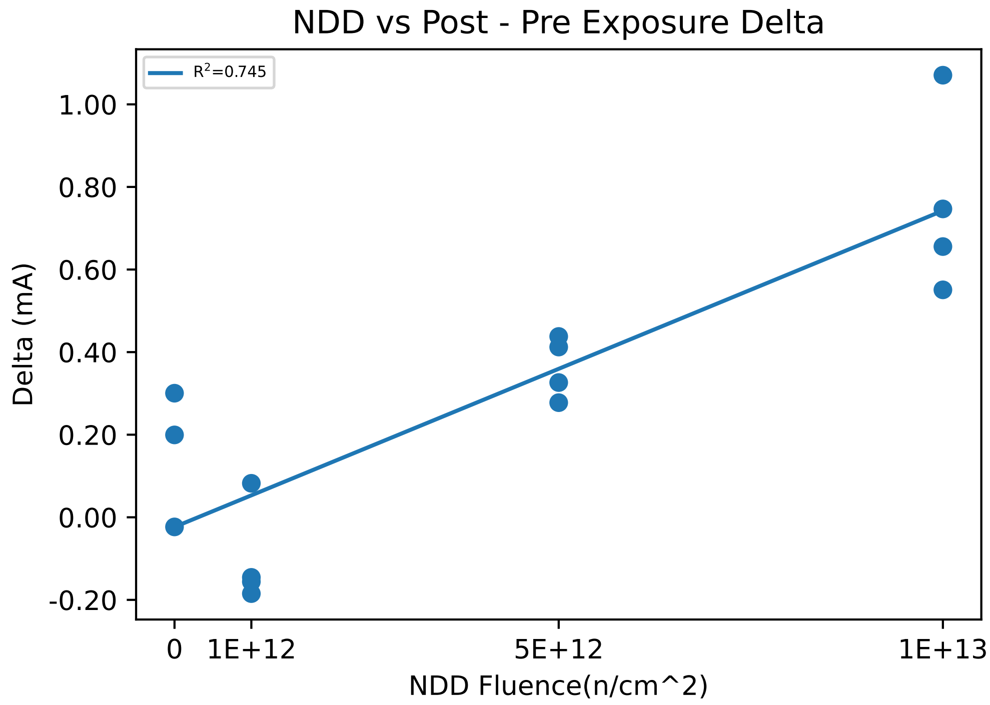
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	142.74	142.74	-0.0017
2	1e+12	NDD	137.72	137.71	-0.0172
3	1e+12	NDD	137.06	137.06	0.0018
4	1e+12	NDD	139.06	139.27	0.2102
5	5e+12	NDD	138.98	139.61	0.6281
6	5e+12	NDD	138.37	138.96	0.5854
7	5e+12	NDD	137.02	137.63	0.6103
8	5e+12	NDD	139.44	139.94	0.4995
9	1e+13	NDD	140.5	141.39	0.8972
10	1e+13	NDD	142.4	143.87	1.4709
11	1e+13	NDD	139.92	140.85	0.9335
12	1e+13	NDD	138.75	139.86	1.1155
13	0	CORRELATION	139.46	139.82	0.3655
14	0	CORRELATION	137.76	138.05	0.2849
15	0	CORRELATION	138.61	138.81	0.1988

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	137.76	138.61	139.46	0.8479	138.05	138.89	139.82	0.89103	0.1988	0.28307	0.3655	0.083365
1e+12	137.06	139.15	142.74	2.5385	137.06	139.19	142.74	2.5402	-0.0172	0.048275	0.2102	0.10827
5e+12	137.02	138.45	139.44	1.0486	137.63	139.03	139.94	1.0186	0.4995	0.58082	0.6281	0.056975
1e+13	138.75	140.39	142.4	1.5255	139.86	141.49	143.87	1.7071	0.8972	1.1043	1.4709	0.26241

Device Test: 15.34 VLDO|ILIM_VLDO_SWEEP/VLDO/5.5/5.5/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_PLUS_1





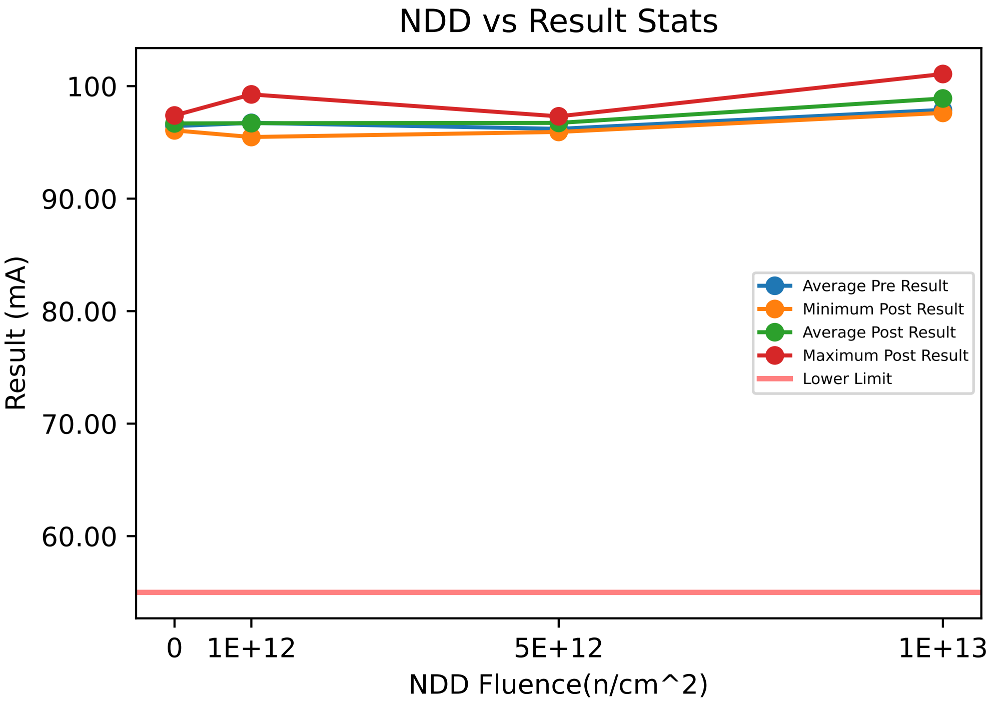
Test Results (Lower Limit = 55.0 (mA))

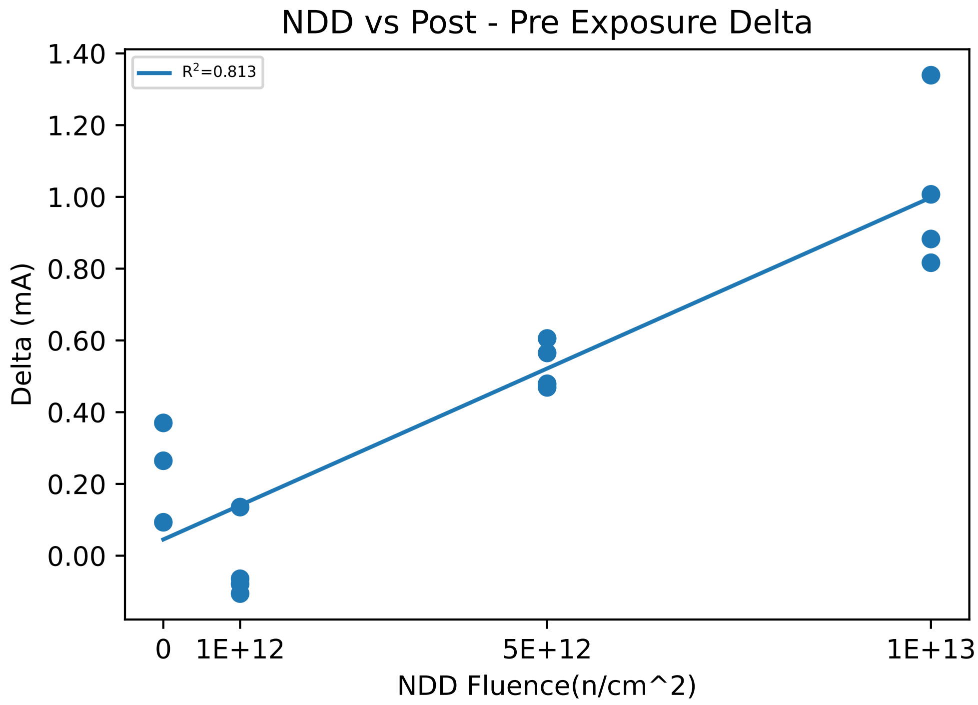
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	94.049	93.893	-0.1561
2	1e+12	NDD	90.203	90.057	-0.1455
3	1e+12	NDD	90.186	90.002	-0.1848
4	1e+12	NDD	91.003	91.085	0.0823
5	5e+12	NDD	91.008	91.446	0.4379
6	5e+12	NDD	90.733	91.01	0.2776
7	5e+12	NDD	89.991	90.404	0.4123
8	5e+12	NDD	91.454	91.78	0.3263
9	1e+13	NDD	92.027	92.578	0.5508
10	1e+13	NDD	94.341	95.412	1.0706
11	1e+13	NDD	92.105	92.761	0.6556
12	1e+13	NDD	91.192	91.939	0.7468
13	0	CORRELATION	91.515	91.815	0.3005
14	0	CORRELATION	90.491	90.69	0.1995
15	0	CORRELATION	91.082	91.059	-0.0233

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.491	91.029	91.515	0.51402	90.69	91.188	91.815	0.57344	-0.0233	0.1589	0.3005	0.16567
1e+12	90.186	91.36	94.049	1.8327	90.002	91.259	93.893	1.8252	-0.1848	-0.10102	0.0823	0.12334
5e+12	89.991	90.796	91.454	0.61339	90.404	91.16	91.78	0.59452	0.2776	0.36352	0.4379	0.074564
1e+13	91.192	92.416	94.341	1.3483	91.939	93.172	95.412	1.5342	0.5508	0.75595	1.0706	0.22453

Device Test: 15.35 VLDO|ILIM_VLDO_SWEEP/VLDO/6/6/0/0/5/500kHz//@V_LDO_ILIM_5_PLUS_1





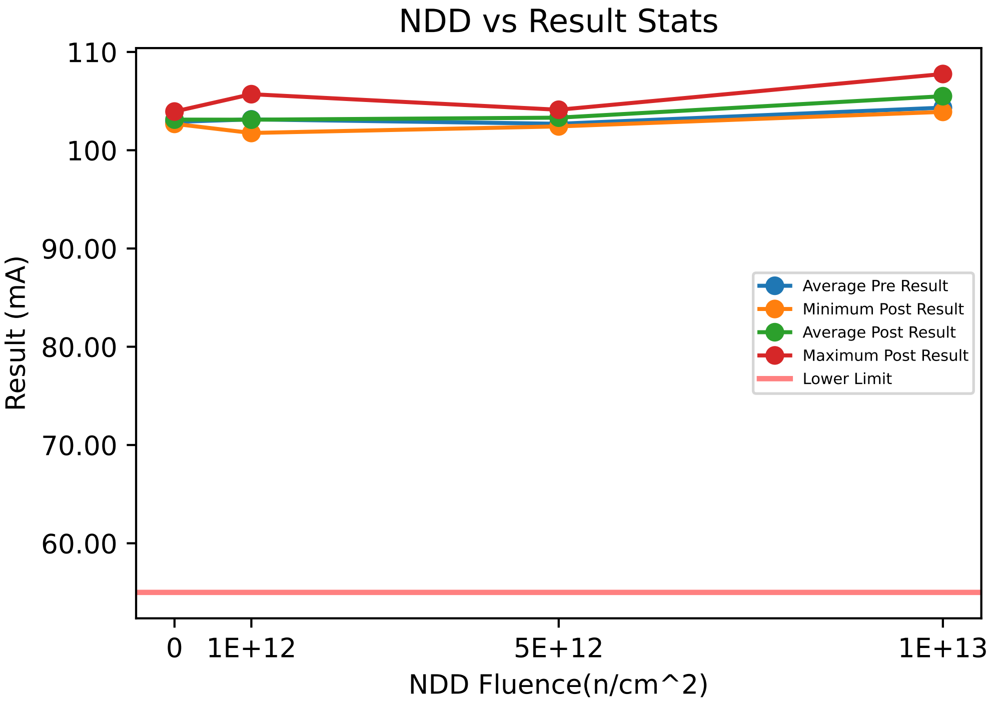
Test Results (Lower Limit = 55.0 (mA))

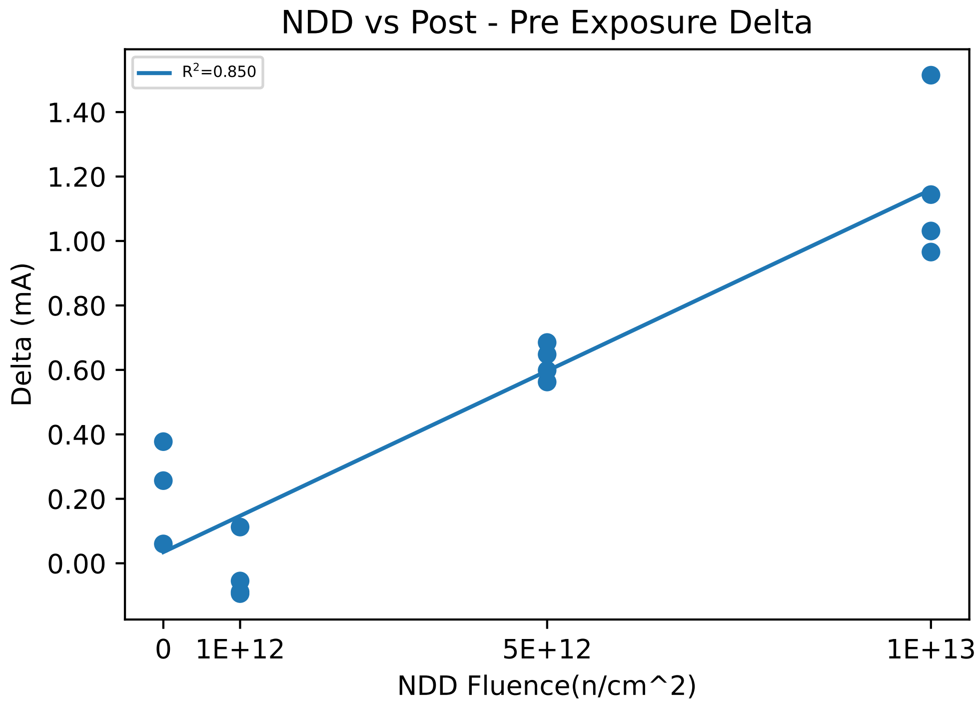
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	99.372	99.266	-0.1056
2	1e+12	NDD	95.542	95.478	-0.0643
3	1e+12	NDD	95.678	95.599	-0.0787
4	1e+12	NDD	96.359	96.494	0.1355
5	5e+12	NDD	96.401	97.007	0.6055
6	5e+12	NDD	96.212	96.681	0.4691
7	5e+12	NDD	95.365	95.93	0.5651
8	5e+12	NDD	96.839	97.318	0.4791
9	1e+13	NDD	97.774	98.59	0.8165
10	1e+13	NDD	99.741	101.08	1.3392
11	1e+13	NDD	97.445	98.327	0.8827
12	1e+13	NDD	96.616	97.623	1.0071
13	0	CORRELATION	97.023	97.393	0.3701
14	0	CORRELATION	95.804	96.068	0.2646
15	0	CORRELATION	96.511	96.604	0.0932

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.804	96.446	97.023	0.61246	96.068	96.689	97.393	0.66661	0.0932	0.24263	0.3701	0.13975
1e+12	95.542	96.738	99.372	1.7921	95.478	96.709	99.266	1.7638	-0.1056	-0.028275	0.1355	0.11052
5e+12	95.365	96.204	96.839	0.61819	95.93	96.734	97.318	0.59582	0.4691	0.5297	0.6055	0.066412
1e+13	96.616	97.894	99.741	1.3245	97.623	98.905	101.08	1.5066	0.8165	1.0114	1.3392	0.23239

Device Test: 15.36 VLDO|ILIM_VLDO_SWEEP/VLDO/6.5/6.5/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_PLUS_1





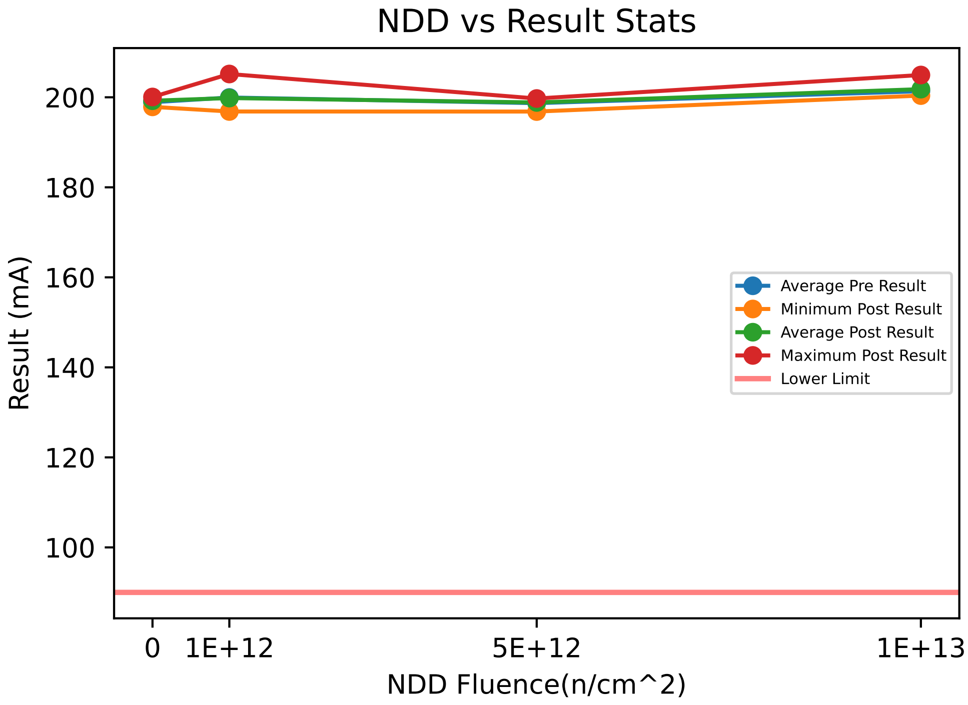
Test Results (Lower Limit = 55.0 (mA))

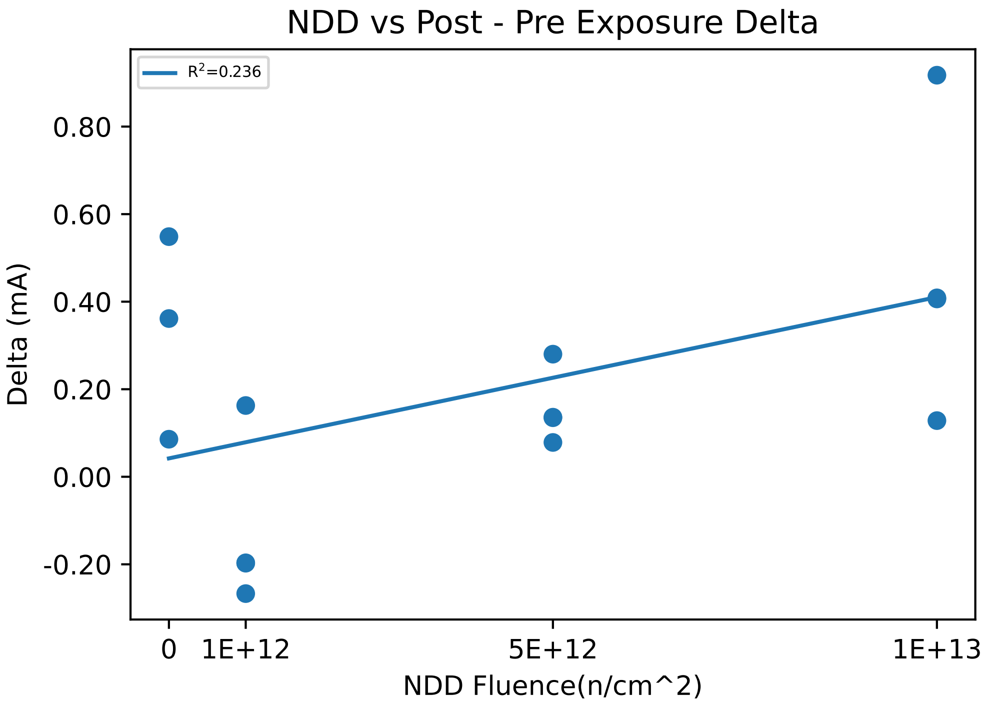
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	105.8	105.7	-0.0941
2	1e+12	NDD	102.17	102.12	-0.055
3	1e+12	NDD	101.84	101.76	-0.0889
4	1e+12	NDD	102.74	102.86	0.1124
5	5e+12	NDD	103.09	103.78	0.685
6	5e+12	NDD	102.37	102.94	0.5625
7	5e+12	NDD	101.78	102.42	0.6479
8	5e+12	NDD	103.52	104.12	0.5987
9	1e+13	NDD	104.22	105.18	0.9656
10	1e+13	NDD	106.24	107.76	1.5144
11	1e+13	NDD	104.11	105.14	1.031
12	1e+13	NDD	102.76	103.9	1.1439
13	0	CORRELATION	103.56	103.94	0.3774
14	0	CORRELATION	102.43	102.68	0.2564
15	0	CORRELATION	102.67	102.73	0.06

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.43	102.89	103.56	0.59585	102.68	103.12	103.94	0.71036	0.06	0.23127	0.3774	0.16019
1e+12	101.84	103.14	105.8	1.8102	101.76	103.11	105.7	1.7895	-0.0941	-0.0314	0.1124	0.097422
5e+12	101.78	102.69	103.52	0.77234	102.42	103.31	104.12	0.77475	0.5625	0.62353	0.685	0.053894
1e+13	102.76	104.33	106.24	1.4359	103.9	105.5	107.76	1.6198	0.9656	1.1637	1.5144	0.24511

Device Test: 15.37 VLDO|ILIM_VLDO_SWEEP/VLDO/7/7/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_7





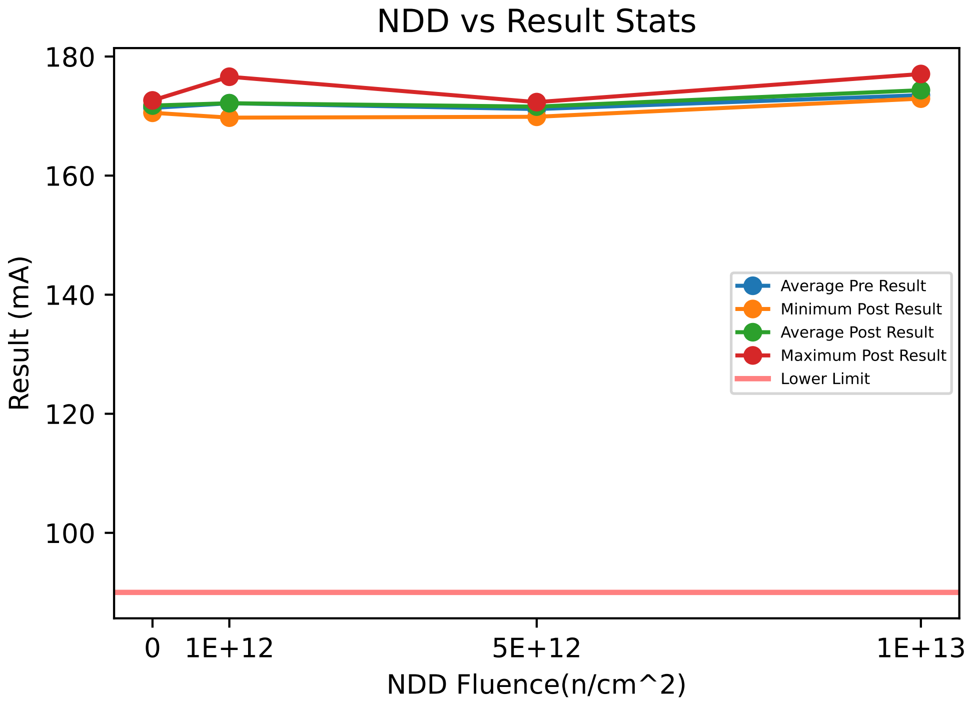
Test Results (Lower Limit = 90.0 (mA))

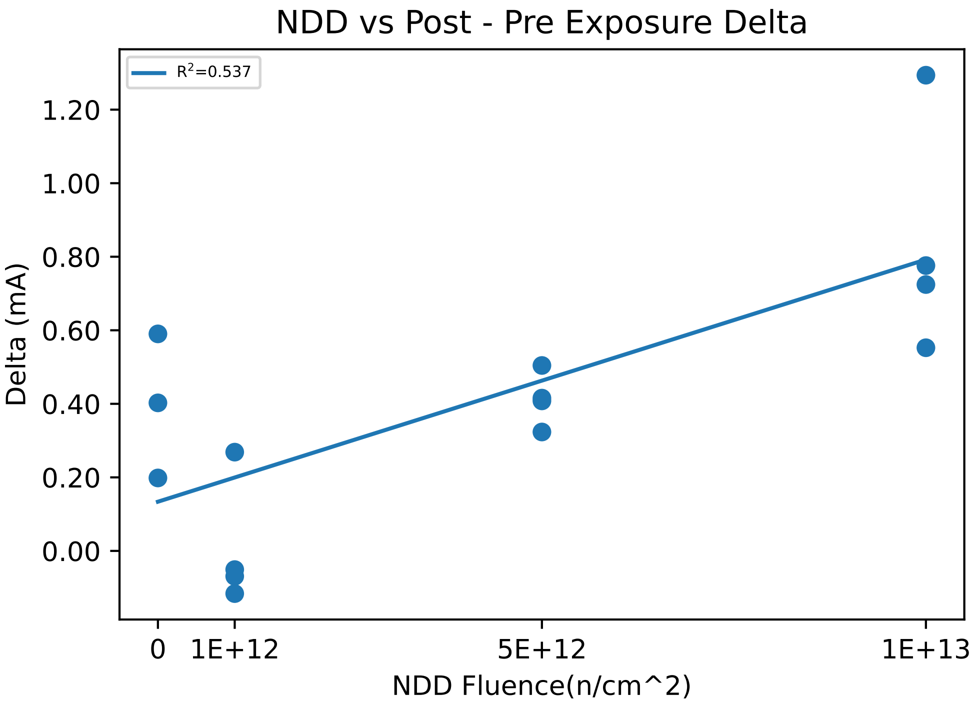
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	205.37	205.17	-0.1974
2	1e+12	NDD	197.37	197.18	-0.1966
3	1e+12	NDD	197.11	196.84	-0.2669
4	1e+12	NDD	199.95	200.12	0.1628
5	5e+12	NDD	199.32	199.46	0.1361
6	5e+12	NDD	199.26	199.4	0.1349
7	5e+12	NDD	196.55	196.83	0.2801
8	5e+12	NDD	199.65	199.73	0.0784
9	1e+13	NDD	200.79	200.91	0.1283
10	1e+13	NDD	204.03	204.95	0.9174
11	1e+13	NDD	200.57	200.98	0.4087
12	1e+13	NDD	199.97	200.38	0.4063
13	0	CORRELATION	199.52	200.07	0.5486
14	0	CORRELATION	197.51	197.88	0.3615
15	0	CORRELATION	199.67	199.76	0.0858

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	197.51	198.9	199.67	1.2047	197.88	199.23	200.07	1.1865	0.0858	0.33197	0.5486	0.23281
1e+12	197.11	199.95	205.37	3.8334	196.84	199.83	205.17	3.8553	-0.2669	-0.12453	0.1628	0.19436
5e+12	196.55	198.7	199.65	1.4407	196.83	198.85	199.73	1.3564	0.0784	0.15738	0.2801	0.086132
1e+13	199.97	201.34	204.03	1.8269	200.38	201.81	204.95	2.1129	0.1283	0.46518	0.9174	0.32896

Device Test: 15.38 VLDO|ILIM_VLDO_SWEEP/VLDO/7/7/0/0/5/500kHz//@V_LDO_ILIM_5_7





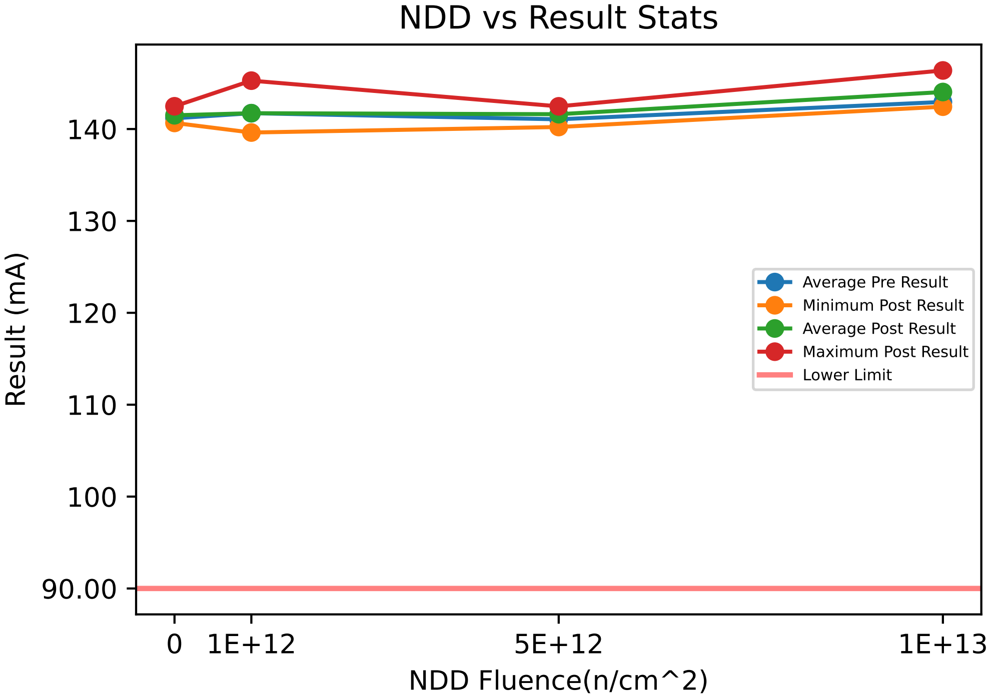
Test Results (Lower Limit = 90.0 (mA))

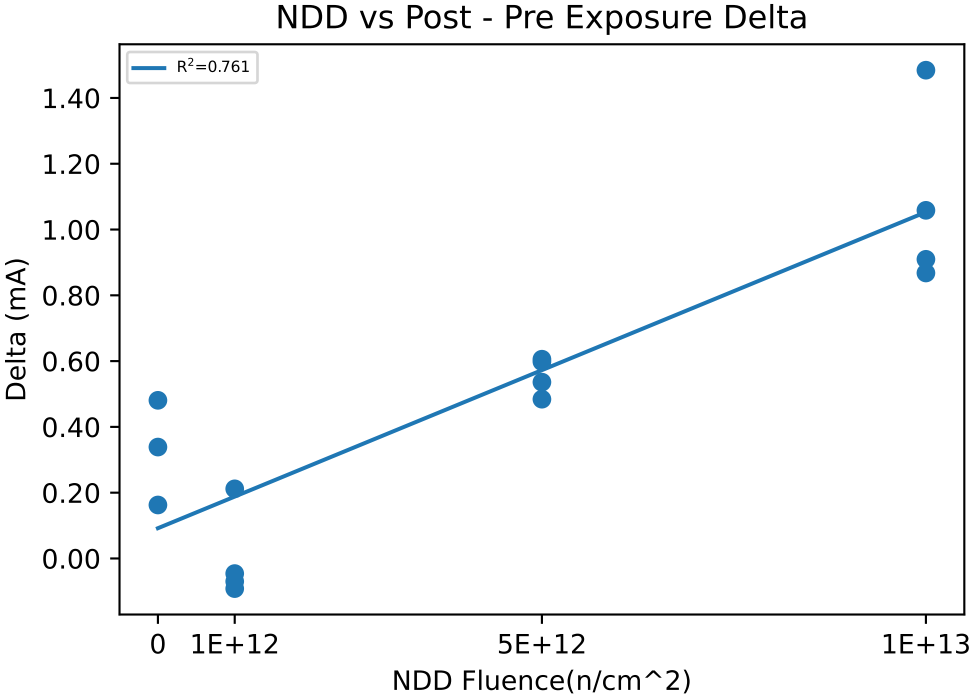
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	176.66	176.61	-0.0508
2	1e+12	NDD	170.01	169.94	-0.069
3	1e+12	NDD	169.85	169.73	-0.1161
4	1e+12	NDD	172.09	172.36	0.2686
5	5e+12	NDD	171.7	172.11	0.408
6	5e+12	NDD	171.6	172.01	0.4155
7	5e+12	NDD	169.37	169.88	0.5043
8	5e+12	NDD	172.02	172.34	0.3234
9	1e+13	NDD	173.36	173.91	0.5525
10	1e+13	NDD	175.77	177.06	1.2937
11	1e+13	NDD	172.75	173.47	0.7244
12	1e+13	NDD	172.15	172.93	0.776
13	0	CORRELATION	172.04	172.63	0.5902
14	0	CORRELATION	170.15	170.55	0.4026
15	0	CORRELATION	171.91	172.11	0.1984

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	170.15	171.37	172.04	1.0566	170.55	171.76	172.63	1.0812	0.1984	0.39707	0.5902	0.19596
1e+12	169.85	172.15	176.66	3.1716	169.73	172.16	176.61	3.1942	-0.1161	0.008175	0.2686	0.17578
5e+12	169.37	171.17	172.02	1.2128	169.88	171.59	172.34	1.1469	0.3234	0.4128	0.5043	0.073926
1e+13	172.15	173.51	175.77	1.5879	172.93	174.34	177.06	1.8581	0.5525	0.83665	1.2937	0.31933

Device Test: 15.39 VLDO|ILIM_VLDO_SWEEP/VLDO/7/7/0/0/5.5/500kHz//@V_LDO_ILIM_5P5_7





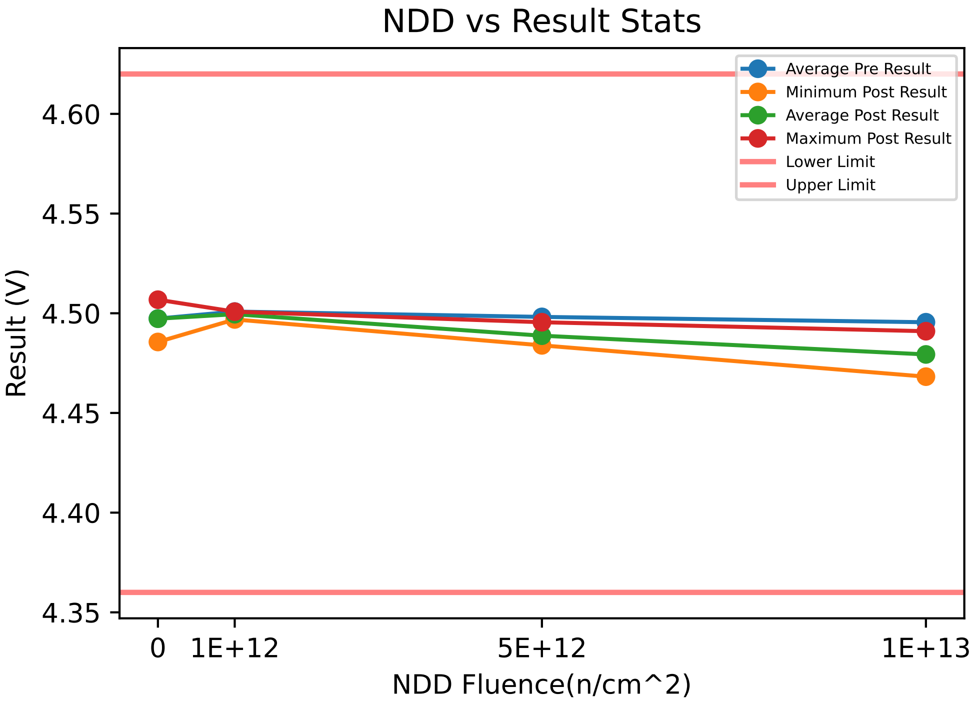
Test Results (Lower Limit = 90.0 (mA))

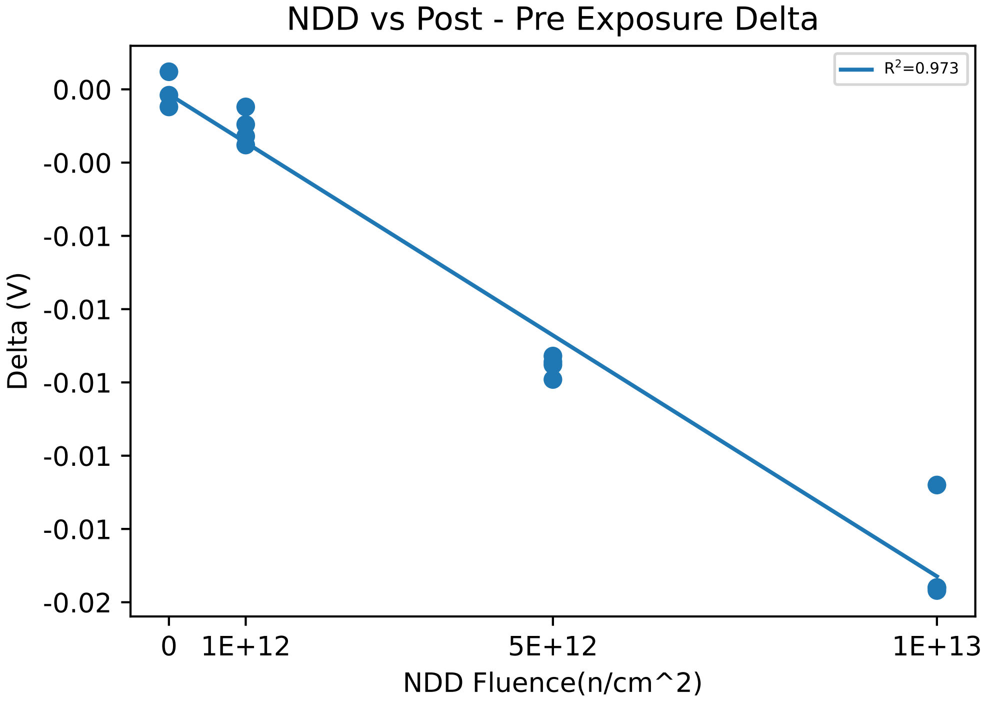
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.31	145.26	-0.0459
2	1e+12	NDD	140.29	140.2	-0.0916
3	1e+12	NDD	139.69	139.62	-0.0699
4	1e+12	NDD	141.6	141.81	0.2117
5	5e+12	NDD	141.61	142.2	0.5983
6	5e+12	NDD	141.02	141.56	0.536
7	5e+12	NDD	139.61	140.22	0.6058
8	5e+12	NDD	141.99	142.47	0.4842
9	1e+13	NDD	143.04	143.9	0.8679
10	1e+13	NDD	144.89	146.38	1.4844
11	1e+13	NDD	142.49	143.4	0.9095
12	1e+13	NDD	141.37	142.43	1.0584
13	0	CORRELATION	141.99	142.47	0.4808
14	0	CORRELATION	140.33	140.67	0.3387
15	0	CORRELATION	141.18	141.35	0.1626

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.33	141.17	141.99	0.83366	140.67	141.5	142.47	0.91373	0.1626	0.32737	0.4808	0.1594
1e+12	139.69	141.72	145.31	2.5218	139.62	141.72	145.26	2.5367	-0.0916	0.001075	0.2117	0.14165
5e+12	139.61	141.06	141.99	1.04	140.22	141.61	142.47	1.0043	0.4842	0.55608	0.6058	0.057226
1e+13	141.37	142.95	144.89	1.4685	142.43	144.03	146.38	1.6798	0.8679	1.08	1.4844	0.2817

Device Test: 15.4 VLDO|V_VLDO/VLDO/12/12/0/0/4.5/500kHz//@V_LDO_4P5





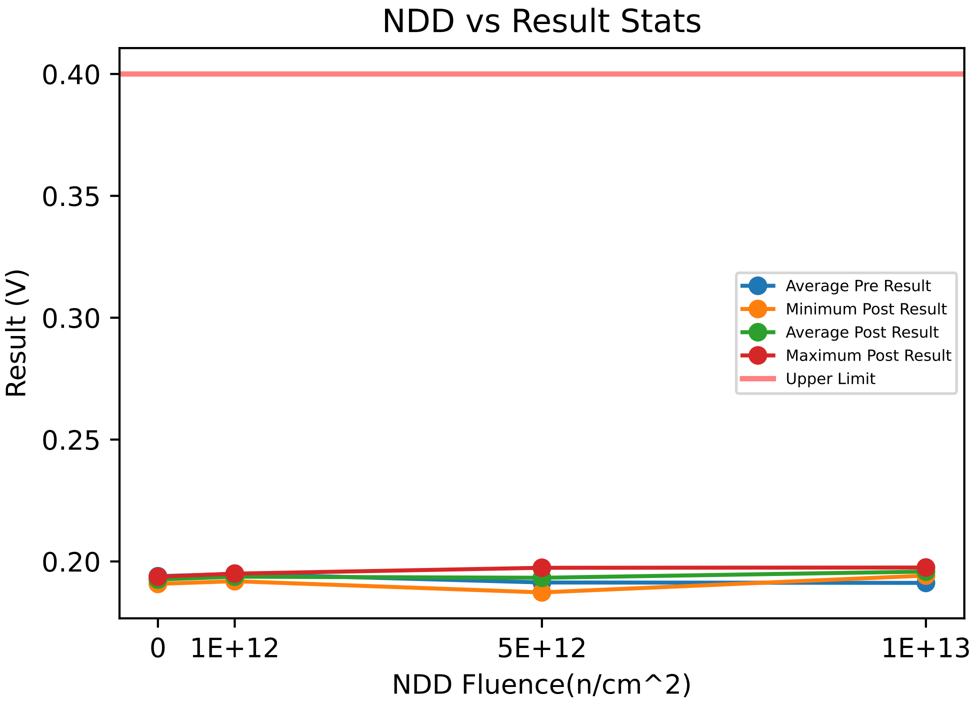
Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

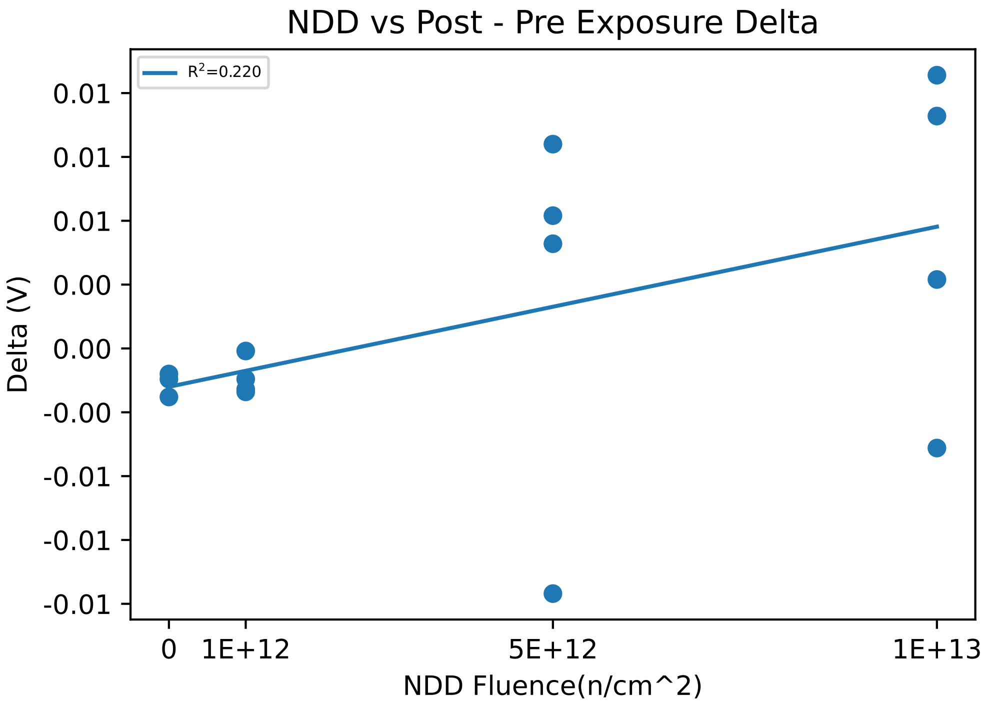
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.5013	4.4997	-0.0016
2	1e+12	NDD	4.4975	4.4969	-0.0006
3	1e+12	NDD	4.5026	4.5007	-0.0019
4	1e+12	NDD	4.502	4.5008	-0.0012
5	5e+12	NDD	4.499	4.4891	-0.0099
6	5e+12	NDD	4.5049	4.4955	-0.0094
7	5e+12	NDD	4.4956	4.4865	-0.0091
8	5e+12	NDD	4.4932	4.4839	-0.0093
9	1e+13	NDD	4.4852	4.4682	-0.017
10	1e+13	NDD	4.4911	4.474	-0.0171
11	1e+13	NDD	4.4977	4.4842	-0.0135
12	1e+13	NDD	4.508	4.491	-0.017
13	0	CORRELATION	4.4858	4.4856	-0.0002
14	0	CORRELATION	4.4988	4.4994	0.0006
15	0	CORRELATION	4.5074	4.5068	-0.0006

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4858	4.4973	4.5074	0.010874	4.4856	4.4973	4.5068	0.01076	-0.0006	-6.6667e-05	0.0006	0.00061101
1e+12	4.4975	4.5008	4.5026	0.0022956	4.4969	4.4995	4.5008	0.0018191	-0.0019	-0.001325	-0.0006	0.00056199
5e+12	4.4932	4.4982	4.5049	0.0050757	4.4839	4.4887	4.4955	0.0049756	-0.0099	-0.009425	-0.0091	0.00034034
1e+13	4.4852	4.4955	4.508	0.0097731	4.4682	4.4794	4.491	0.010201	-0.0171	-0.01615	-0.0135	0.0017673

Device Test: 15.40 VLDO|VDO_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_DO_5





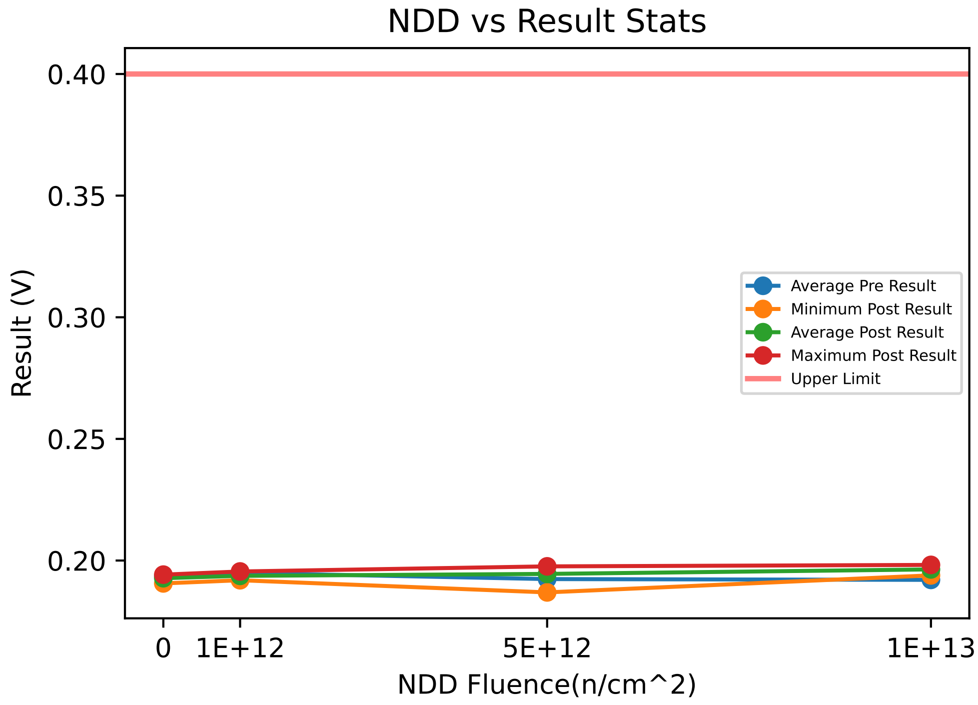
Test Results (Upper Limit = 0.4 (V))

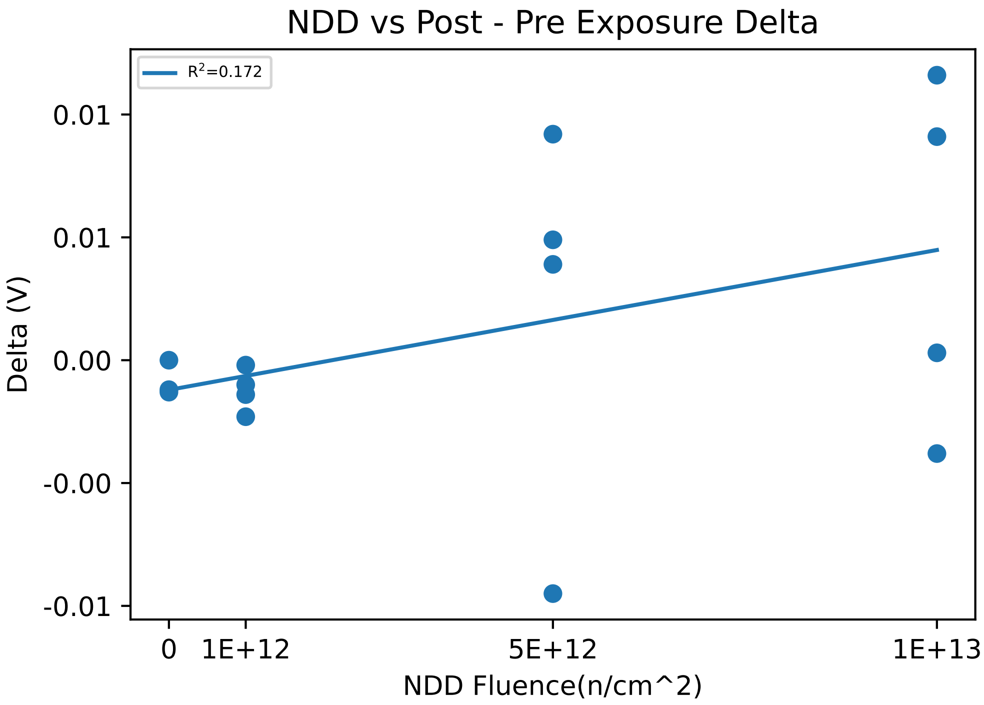
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1966	0.195	-0.0016
2	1e+12	NDD	0.1932	0.1931	-0.0001
3	1e+12	NDD	0.1962	0.195	-0.0012
4	1e+12	NDD	0.1936	0.1919	-0.0017
5	5e+12	NDD	0.1933	0.1974	0.0041
6	5e+12	NDD	0.1969	0.1873	-0.0096
7	5e+12	NDD	0.1884	0.1936	0.0052
8	5e+12	NDD	0.1869	0.1949	0.008
9	1e+13	NDD	0.1868	0.1975	0.0107
10	1e+13	NDD	0.1862	0.1953	0.0091
11	1e+13	NDD	0.1937	0.1964	0.0027
12	1e+13	NDD	0.1981	0.1942	-0.0039
13	0	CORRELATION	0.192	0.1908	-0.0012
14	0	CORRELATION	0.1947	0.1937	-0.001
15	0	CORRELATION	0.1951	0.1932	-0.0019

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.192	0.19393	0.1951	0.0016862	0.1908	0.19257	0.1937	0.0015503	-0.0019	-0.0013667	-0.001	0.00047258
1e+12	0.1932	0.1949	0.1966	0.0017474	0.1919	0.19375	0.195	0.0015242	-0.0017	-0.00115	-0.0001	0.00073258
5e+12	0.1869	0.19138	0.1969	0.0045865	0.1873	0.1933	0.1974	0.0042996	-0.0096	0.001925	0.008	0.0078568
1e+13	0.1862	0.1912	0.1981	0.0057219	0.1942	0.19585	0.1975	0.0014201	-0.0039	0.00465	0.0107	0.0066661

Device Test: 15.41 VLDO|VDO_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_DO_5





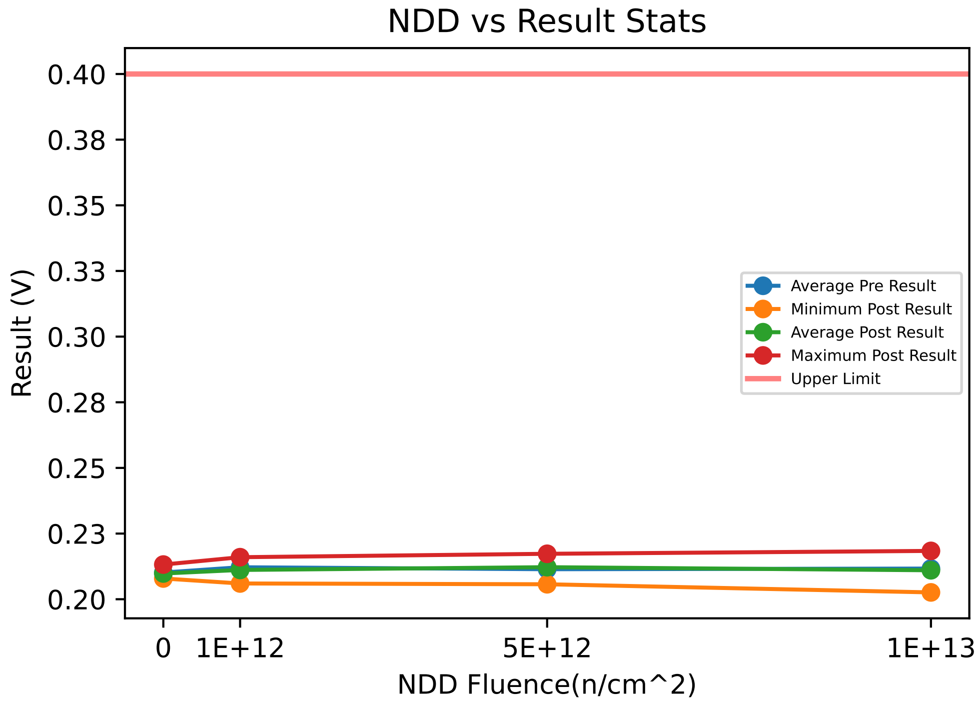
Test Results (Upper Limit = 0.4 (V))

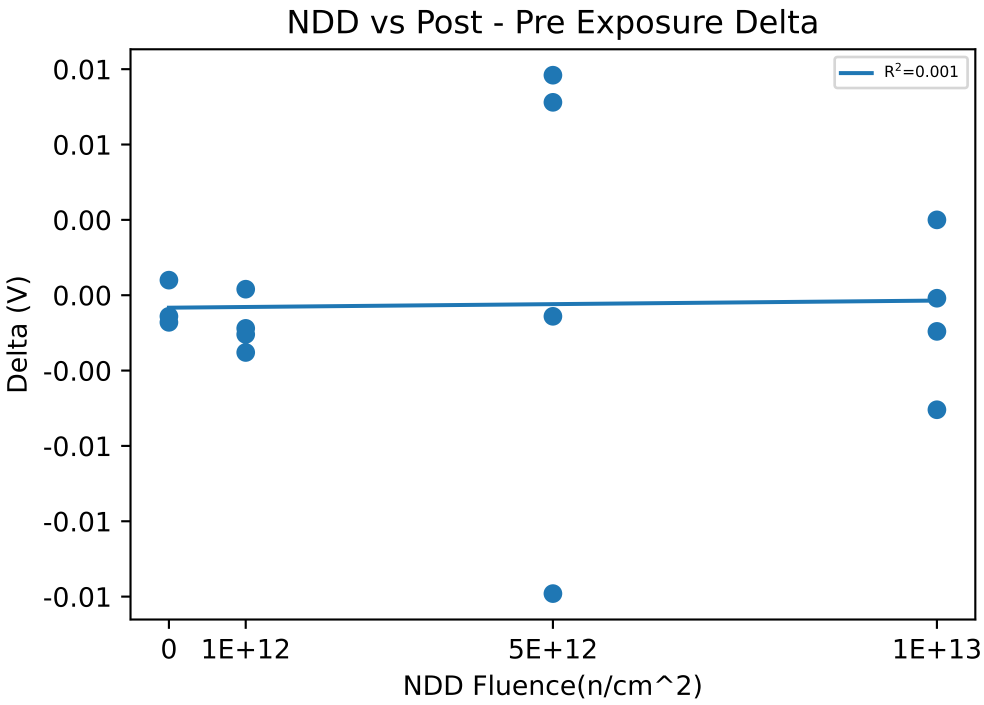
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1965	0.1955	-0.001
2	1e+12	NDD	0.1931	0.1929	-0.0002
3	1e+12	NDD	0.1959	0.1945	-0.0014
4	1e+12	NDD	0.1942	0.1919	-0.0023
5	5e+12	NDD	0.1935	0.1974	0.0039
6	5e+12	NDD	0.1964	0.1869	-0.0095
7	5e+12	NDD	0.1912	0.1961	0.0049
8	5e+12	NDD	0.1884	0.1976	0.0092
9	1e+13	NDD	0.1863	0.1979	0.0116
10	1e+13	NDD	0.1863	0.1954	0.0091
11	1e+13	NDD	0.1979	0.1982	0.0003
12	1e+13	NDD	0.1977	0.1939	-0.0038
13	0	CORRELATION	0.1919	0.1906	-0.0013
14	0	CORRELATION	0.1942	0.1942	0
15	0	CORRELATION	0.1946	0.1934	-0.0012

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1919	0.19357	0.1946	0.0014572	0.1906	0.19273	0.1942	0.0018903	-0.0013	-0.00083333	0	0.00072342
1e+12	0.1931	0.19493	0.1965	0.0015586	0.1919	0.1937	0.1955	0.0016083	-0.0023	-0.001225	-0.0002	0.00087321
5e+12	0.1884	0.19238	0.1964	0.0033984	0.1869	0.1945	0.1976	0.0051101	-0.0095	0.002125	0.0092	0.0080839
1e+13	0.1863	0.19205	0.1979	0.00664	0.1939	0.19635	0.1982	0.0020599	-0.0038	0.0043	0.0116	0.0072558

Device Test: 15.42 VLDO|VDO_VLDO/VLDO/12/12/0/0/5.5/500kHz//@V_LDO_DO_5P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Upper Limit = 0.4 (V))

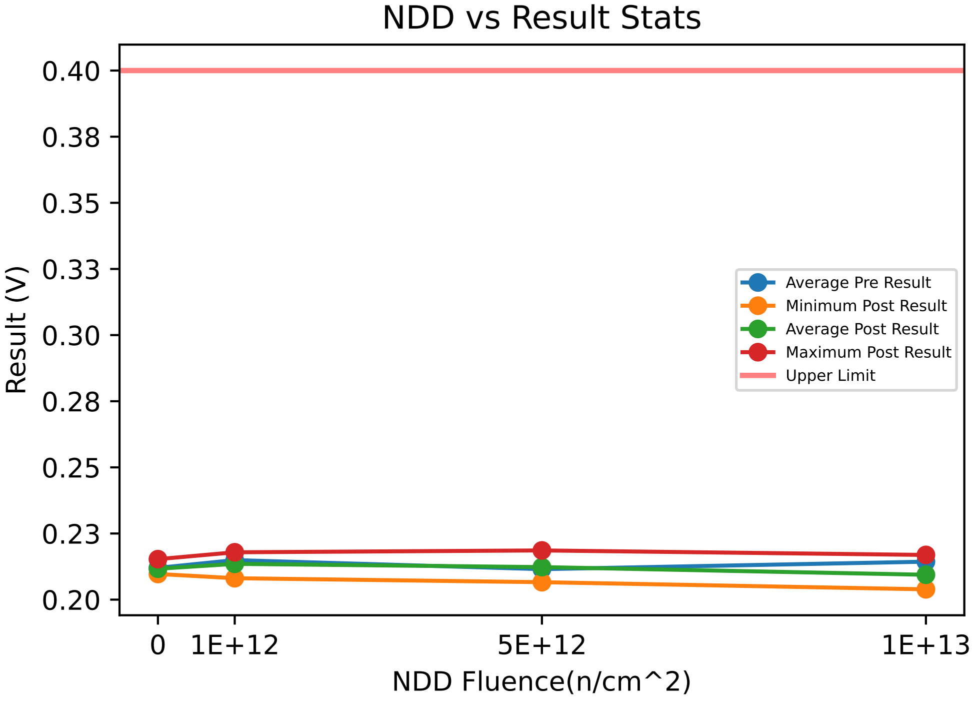
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2173	0.216	-0.0013
2	1e+12	NDD	0.2058	0.206	0.0002
3	1e+12	NDD	0.2153	0.2142	-0.0011
4	1e+12	NDD	0.2103	0.2084	-0.0019
5	5e+12	NDD	0.2063	0.2127	0.0064
6	5e+12	NDD	0.2156	0.2057	-0.0099
7	5e+12	NDD	0.2058	0.2131	0.0073
8	5e+12	NDD	0.218	0.2173	-0.0007
9	1e+13	NDD	0.2071	0.207	-0.0001
10	1e+13	NDD	0.2064	0.2026	-0.0038
11	1e+13	NDD	0.2159	0.2184	0.0025
12	1e+13	NDD	0.2173	0.2161	-0.0012
13	0	CORRELATION	0.2092	0.2083	-0.0009
14	0	CORRELATION	0.2074	0.2079	0.0005
15	0	CORRELATION	0.2139	0.2132	-0.0007

Test Statistics (V)

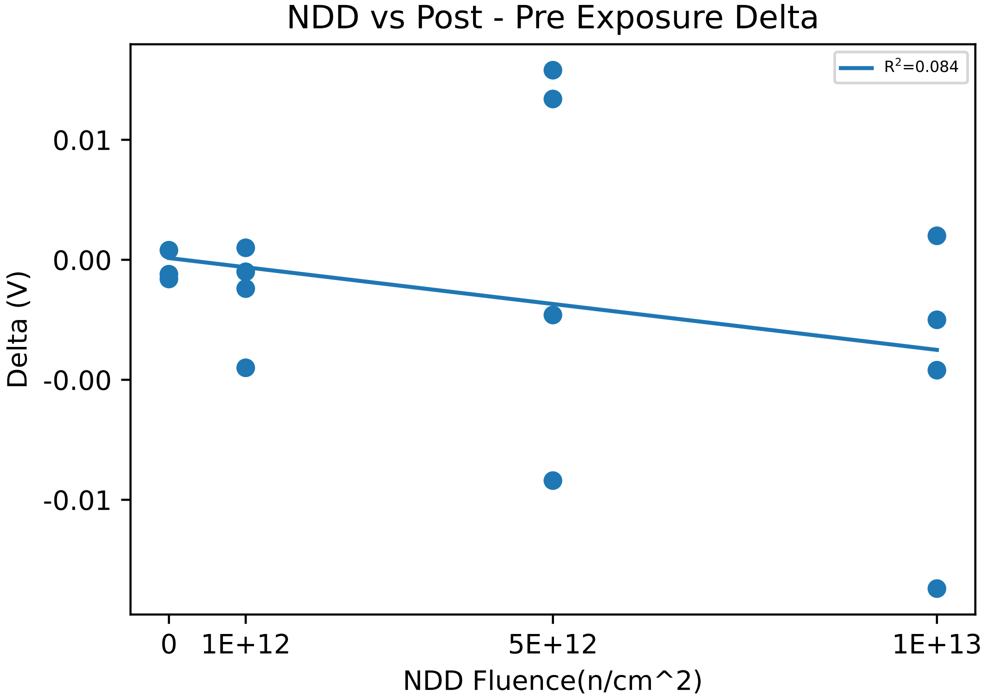
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2074	0.21017	0.2139	0.0033561	0.2079	0.2098	0.2132	0.0029513	-0.0009	-0.00036667	0.0005	0.00075719
1e+12	0.2058	0.21218	0.2173	0.00517	0.206	0.21115	0.216	0.0047226	-0.0019	-0.001025	0.0002	0.00088459
5e+12	0.2058	0.21143	0.218	0.0062867	0.2057	0.2122	0.2173	0.0048069	-0.0099	0.000775	0.0073	0.0079655
1e+13	0.2064	0.21168	0.2173	0.0057227	0.2026	0.21102	0.2184	0.0074683	-0.0038	-0.00065	0.0025	0.0026109

Device Test: 15.43 VLDO|VDO_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_DO_5P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



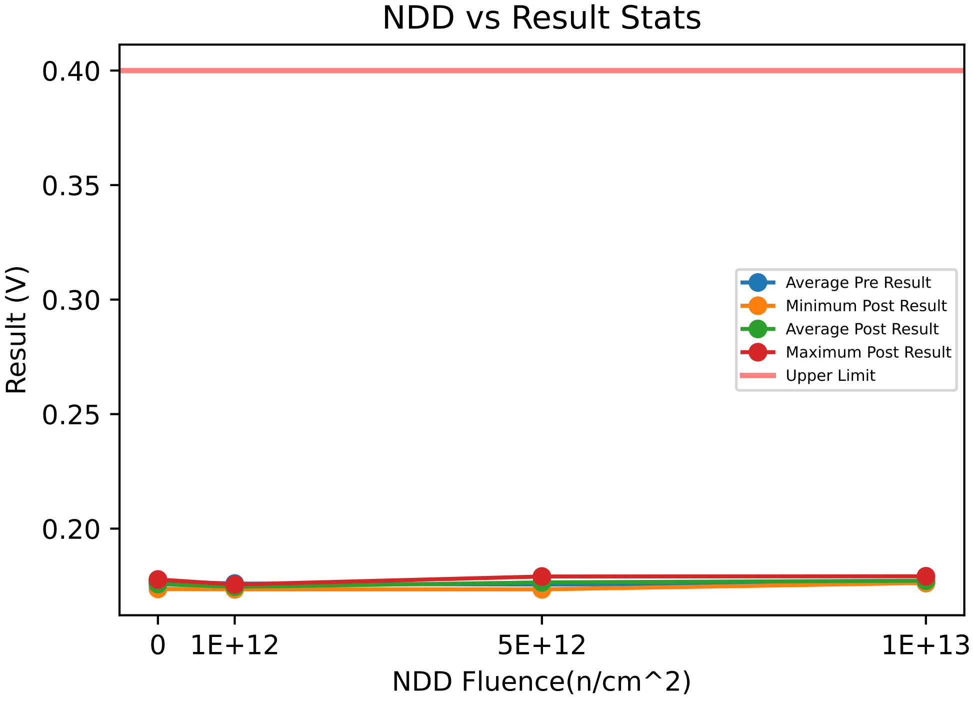
Test Results (Upper Limit = 0.4 (V))

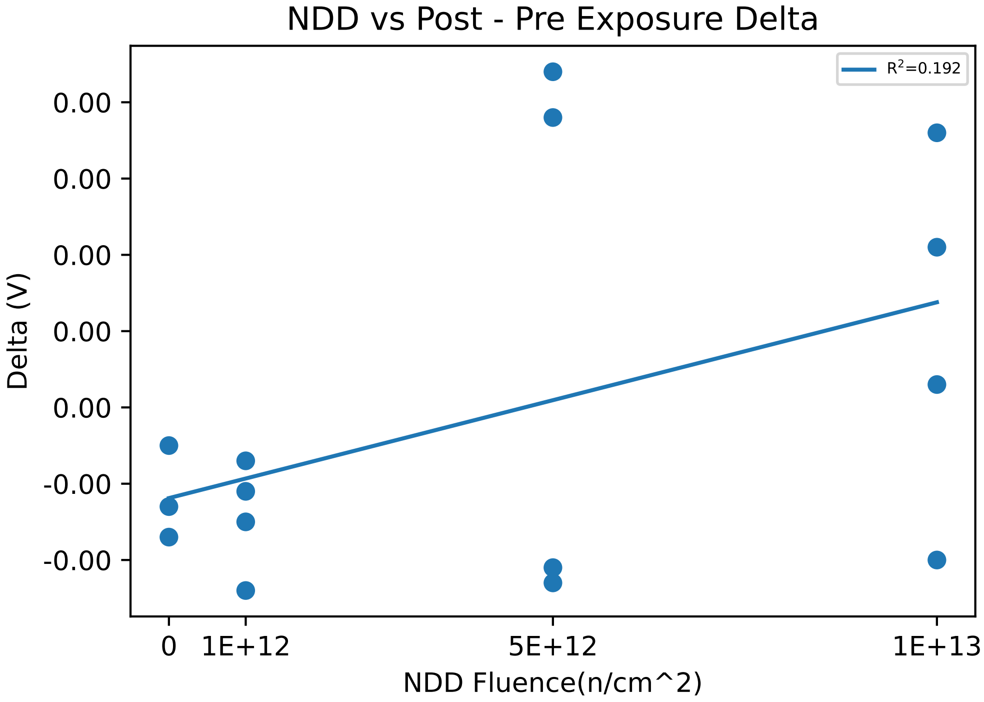
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2191	0.2179	-0.0012
2	1e+12	NDD	0.2076	0.2081	0.0005
3	1e+12	NDD	0.2179	0.2174	-0.0005
4	1e+12	NDD	0.2152	0.2107	-0.0045
5	5e+12	NDD	0.2092	0.2159	0.0067
6	5e+12	NDD	0.2173	0.2081	-0.0092
7	5e+12	NDD	0.2107	0.2186	0.0079
8	5e+12	NDD	0.2089	0.2066	-0.0023
9	1e+13	NDD	0.2095	0.2105	0.001
10	1e+13	NDD	0.2085	0.2039	-0.0046
11	1e+13	NDD	0.22	0.2063	-0.0137
12	1e+13	NDD	0.2194	0.2169	-0.0025
13	0	CORRELATION	0.2108	0.21	-0.0008
14	0	CORRELATION	0.2093	0.2097	0.0004
15	0	CORRELATION	0.2159	0.2153	-0.0006

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2093	0.212	0.2159	0.0034598	0.2097	0.21167	0.2153	0.0031501	-0.0008	-0.00033333	0.0004	0.00064291
1e+12	0.2076	0.21495	0.2191	0.0051643	0.2081	0.21353	0.2179	0.0048842	-0.0045	-0.001425	0.0005	0.0021654
5e+12	0.2089	0.21152	0.2173	0.0039297	0.2066	0.2123	0.2186	0.0058532	-0.0092	0.000775	0.0079	0.0080587
1e+13	0.2085	0.21435	0.22	0.006196	0.2039	0.2094	0.2169	0.0056956	-0.0137	-0.00495	0.001	0.006274

Device Test: 15.44 VLDO|VDO_VLDO/VLDO/4.5/4.5/0/0/4.5/500kHz//@V_LDO_DO_4P5





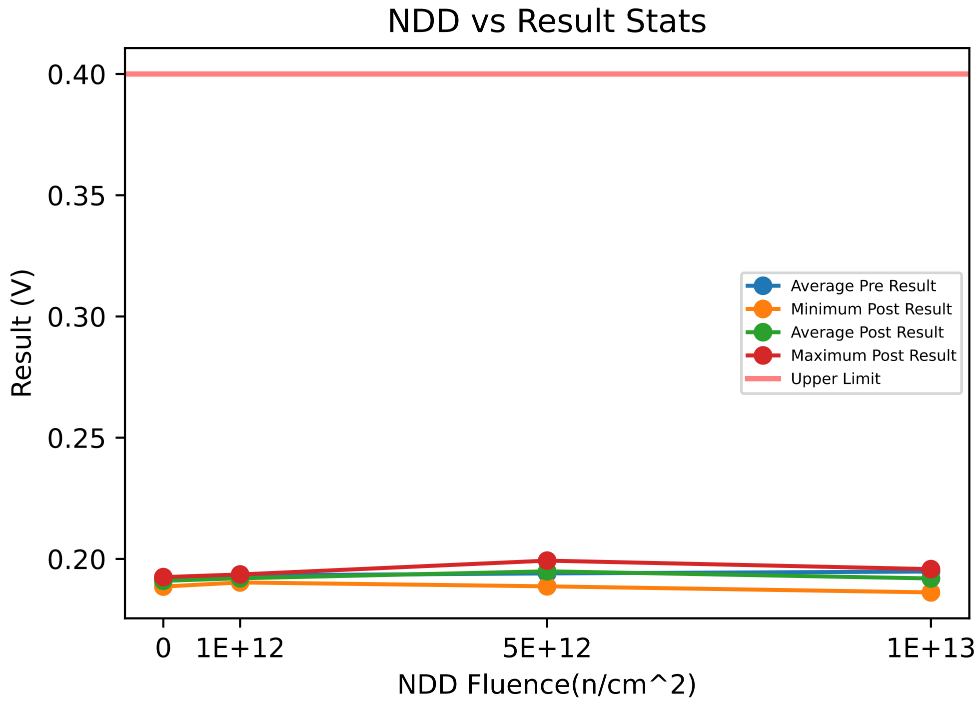
Test Results (Upper Limit = 0.4 (V))

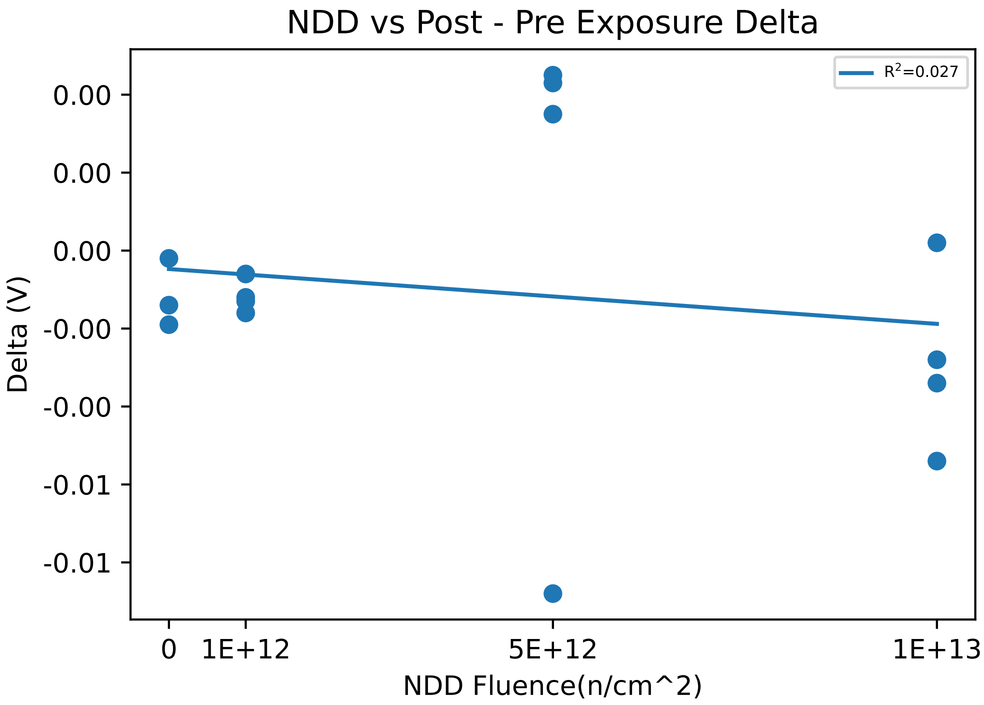
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1765	0.1754	-0.0011
2	1e+12	NDD	0.1763	0.1756	-0.0007
3	1e+12	NDD	0.175	0.1735	-0.0015
4	1e+12	NDD	0.1763	0.1739	-0.0024
5	5e+12	NDD	0.1758	0.1735	-0.0023
6	5e+12	NDD	0.175	0.1788	0.0038
7	5e+12	NDD	0.1768	0.1747	-0.0021
8	5e+12	NDD	0.1747	0.1791	0.0044
9	1e+13	NDD	0.1792	0.1772	-0.002
10	1e+13	NDD	0.1742	0.1763	0.0021
11	1e+13	NDD	0.1761	0.1764	0.0003
12	1e+13	NDD	0.1756	0.1792	0.0036
13	0	CORRELATION	0.1754	0.1737	-0.0017
14	0	CORRELATION	0.1764	0.1759	-0.0005
15	0	CORRELATION	0.1791	0.1778	-0.0013

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1754	0.17697	0.1791	0.001914	0.1737	0.1758	0.1778	0.0020518	-0.0017	-0.0011667	-0.0005	0.00061101
1e+12	0.175	0.17602	0.1765	0.00068981	0.1735	0.1746	0.1756	0.0010551	-0.0024	-0.001425	-0.0007	0.00072744
5e+12	0.1747	0.17558	0.1768	0.00093941	0.1735	0.17652	0.1791	0.0028453	-0.0023	0.00095	0.0044	0.0036465
1e+13	0.1742	0.17628	0.1792	0.0021093	0.1763	0.17728	0.1792	0.0013451	-0.002	0.001	0.0036	0.0024125

Device Test: 15.45 VLDO|VDO_VLDO/VLDO/5/5/0/0/5/500kHz//@V_LDO_DO_5





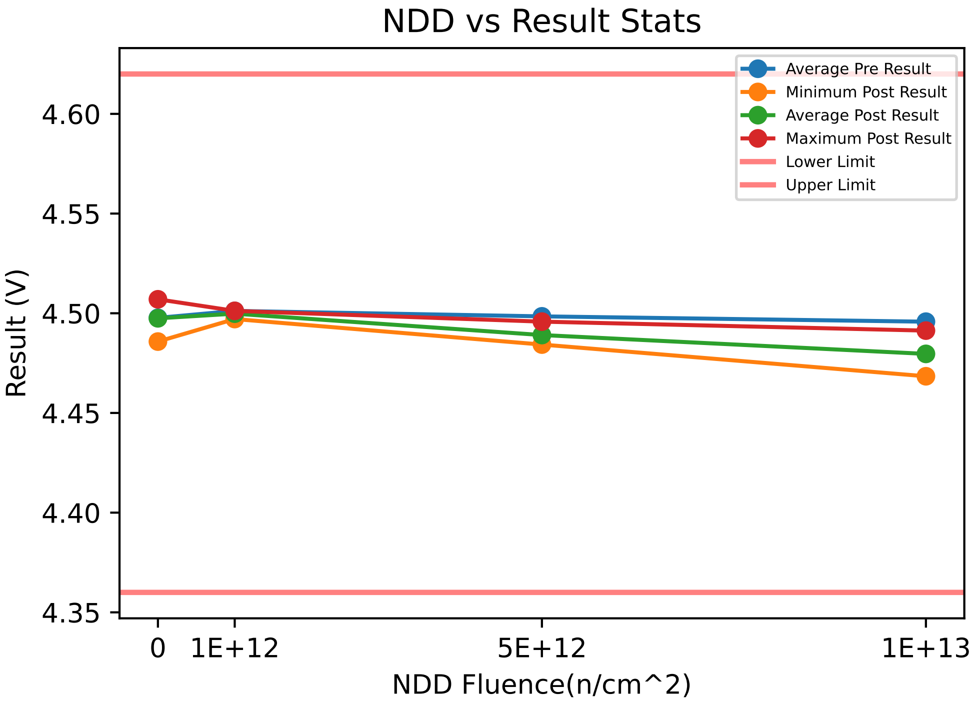
Test Results (Upper Limit = 0.4 (V))

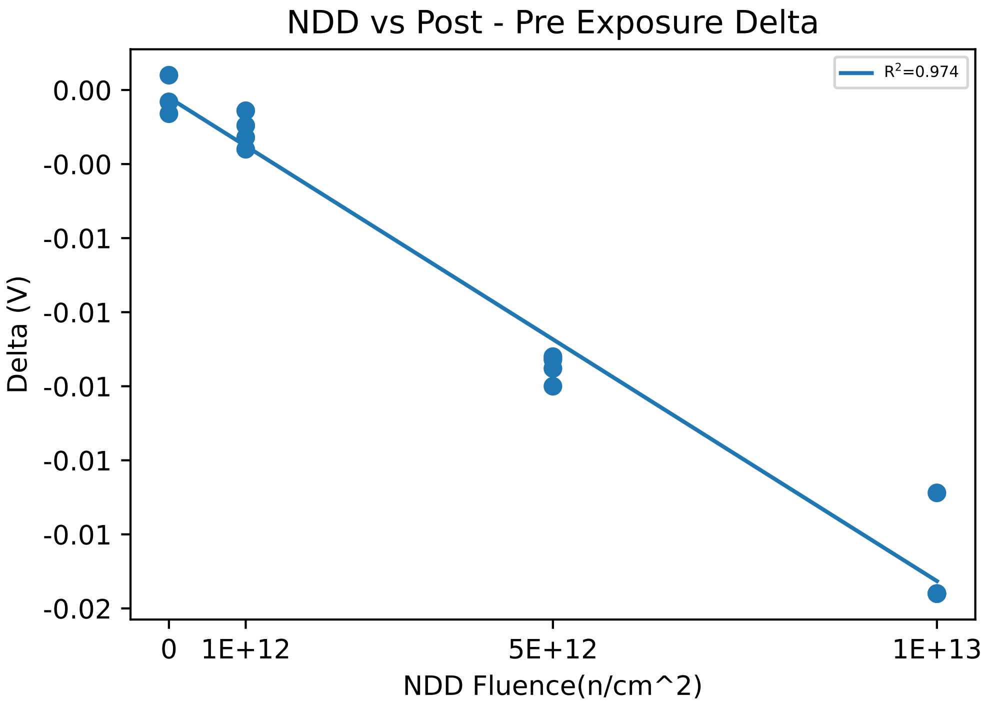
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1949	0.1936	-0.0013
2	1e+12	NDD	0.1918	0.1912	-0.0006
3	1e+12	NDD	0.1942	0.193	-0.0012
4	1e+12	NDD	0.1919	0.1903	-0.0016
5	5e+12	NDD	0.1922	0.1957	0.0035
6	5e+12	NDD	0.195	0.1993	0.0043
7	5e+12	NDD	0.1914	0.1959	0.0045
8	5e+12	NDD	0.1975	0.1887	-0.0088
9	1e+13	NDD	0.1986	0.1958	-0.0028
10	1e+13	NDD	0.1987	0.1933	-0.0054
11	1e+13	NDD	0.186	0.1862	0.0002
12	1e+13	NDD	0.1959	0.1925	-0.0034
13	0	CORRELATION	0.1905	0.1886	-0.0019
14	0	CORRELATION	0.1927	0.1925	-0.0002
15	0	CORRELATION	0.1932	0.1918	-0.0014

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1905	0.19213	0.1932	0.0014364	0.1886	0.19097	0.1925	0.0020793	-0.0019	-0.0011667	-0.0002	0.00087369
1e+12	0.1918	0.1932	0.1949	0.0015853	0.1903	0.19203	0.1936	0.001537	-0.0016	-0.001175	-0.0006	0.00041932
5e+12	0.1914	0.19403	0.1975	0.0027837	0.1887	0.1949	0.1993	0.0044512	-0.0088	0.000875	0.0045	0.0064645
1e+13	0.186	0.1948	0.1987	0.0060083	0.1862	0.19195	0.1958	0.0040829	-0.0054	-0.00285	0.0002	0.0023173

Device Test: 15.5 VLDO|V_VLDO/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_4P5





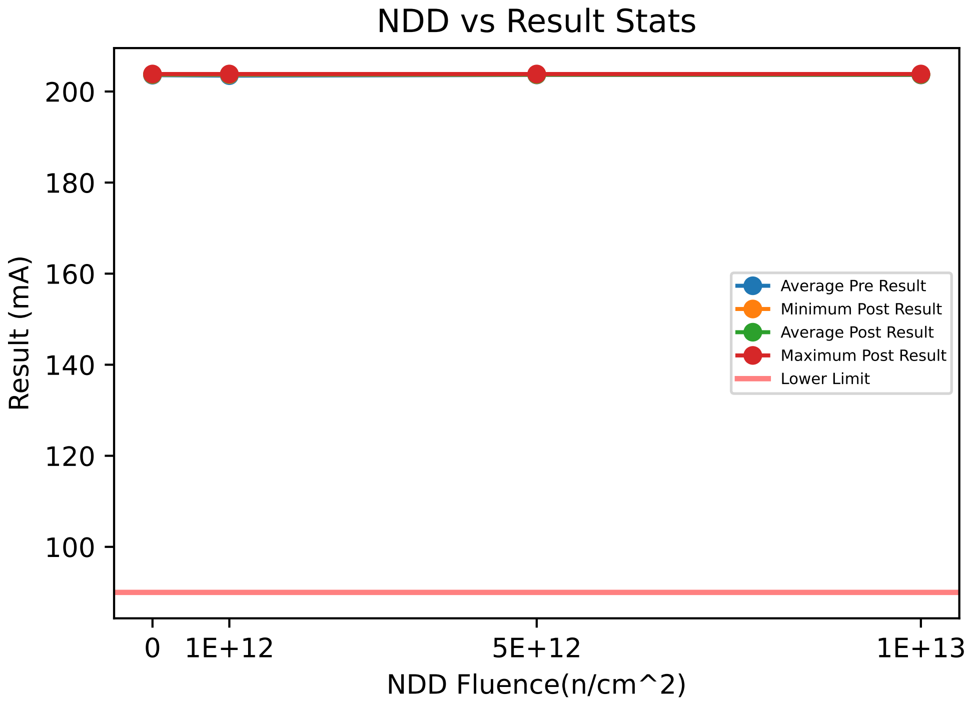
Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

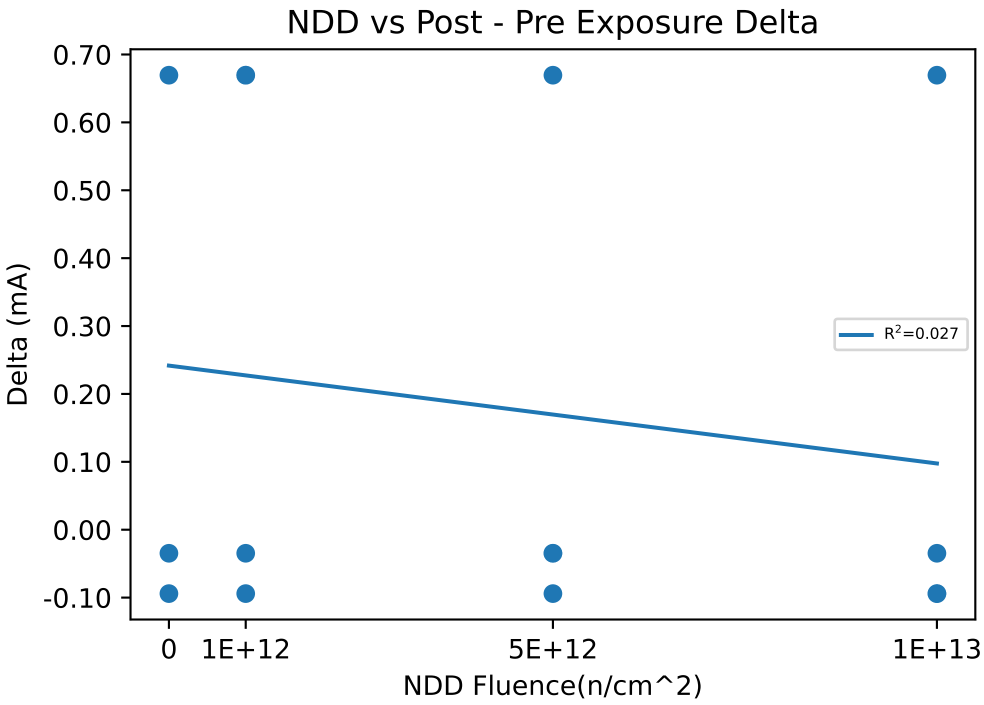
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.5016	4.5	-0.0016
2	1e+12	NDD	4.4978	4.4971	-0.0007
3	1e+12	NDD	4.5029	4.5009	-0.002
4	1e+12	NDD	4.5024	4.5012	-0.0012
5	5e+12	NDD	4.4993	4.4893	-0.01
6	5e+12	NDD	4.5052	4.4958	-0.0094
7	5e+12	NDD	4.4959	4.4869	-0.009
8	5e+12	NDD	4.4934	4.4843	-0.0091
9	1e+13	NDD	4.4854	4.4684	-0.017
10	1e+13	NDD	4.4914	4.4744	-0.017
11	1e+13	NDD	4.498	4.4844	-0.0136
12	1e+13	NDD	4.5083	4.4913	-0.017
13	0	CORRELATION	4.4862	4.4858	-0.0004
14	0	CORRELATION	4.4991	4.4996	0.0005
15	0	CORRELATION	4.5078	4.507	-0.0008

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4862	4.4977	4.5078	0.010868	4.4858	4.4975	4.507	0.01076	-0.0008	-0.00023333	0.0005	0.00066583
1e+12	4.4978	4.5012	4.5029	0.0023128	4.4971	4.4998	4.5012	0.0018708	-0.002	-0.001375	-0.0007	0.00055603
5e+12	4.4934	4.4985	4.5052	0.0051085	4.4843	4.4891	4.4958	0.0049264	-0.01	-0.009375	-0.009	0.00045
1e+13	4.4854	4.4958	4.5083	0.0098083	4.4684	4.4796	4.4913	0.010205	-0.017	-0.01615	-0.0136	0.0017

Device Test: 15.6 VLDO|ILIM_VLDO/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_7





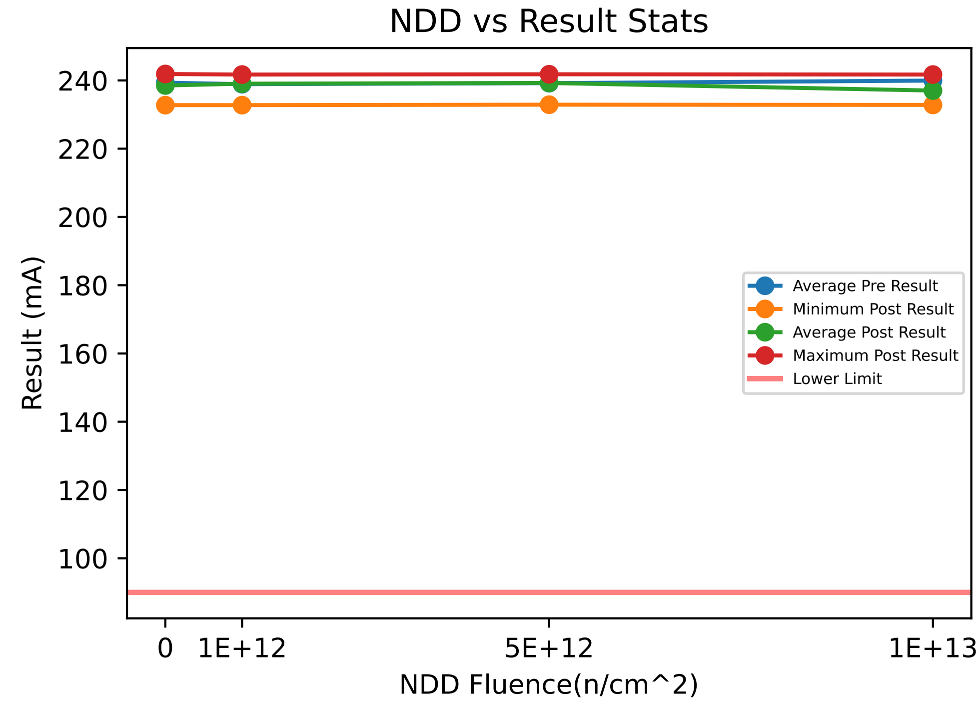
Test Results (Lower Limit = 90.0 (mA))

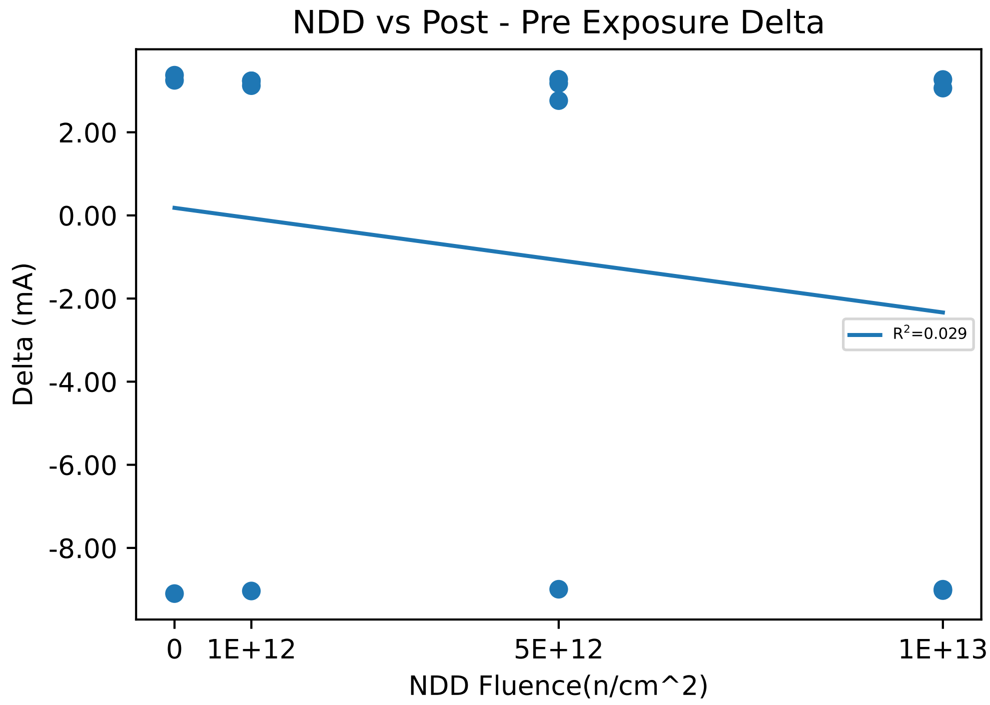
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	203.18	203.84	0.6695
2	1e+12	NDD	203.78	203.75	-0.0347
3	1e+12	NDD	203.79	203.69	-0.0941
4	1e+12	NDD	203.18	203.84	0.6695
5	5e+12	NDD	203.78	203.75	-0.0347
6	5e+12	NDD	203.79	203.69	-0.0941
7	5e+12	NDD	203.18	203.84	0.6695
8	5e+12	NDD	203.78	203.75	-0.0347
9	1e+13	NDD	203.79	203.69	-0.0941
10	1e+13	NDD	203.18	203.84	0.6695
11	1e+13	NDD	203.78	203.75	-0.0347
12	1e+13	NDD	203.79	203.69	-0.0941
13	0	CORRELATION	203.18	203.84	0.6695
14	0	CORRELATION	203.78	203.75	-0.0347
15	0	CORRELATION	203.79	203.69	-0.0941

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	203.18	203.58	203.79	0.35164	203.69	203.76	203.84	0.077132	-0.0941	0.18023	0.6695	0.42476
1e+12	203.18	203.48	203.79	0.35164	203.69	203.78	203.84	0.075486	-0.0941	0.30255	0.6695	0.42441
5e+12	203.18	203.63	203.79	0.30416	203.69	203.76	203.84	0.063375	-0.0941	0.1265	0.6695	0.36308
1e+13	203.18	203.63	203.79	0.30491	203.69	203.74	203.84	0.071825	-0.0941	0.11165	0.6695	0.37295

Device Test: 15.7 VLDO|ILIM_VLDO_SWEEP/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_ILIM_4P5_7





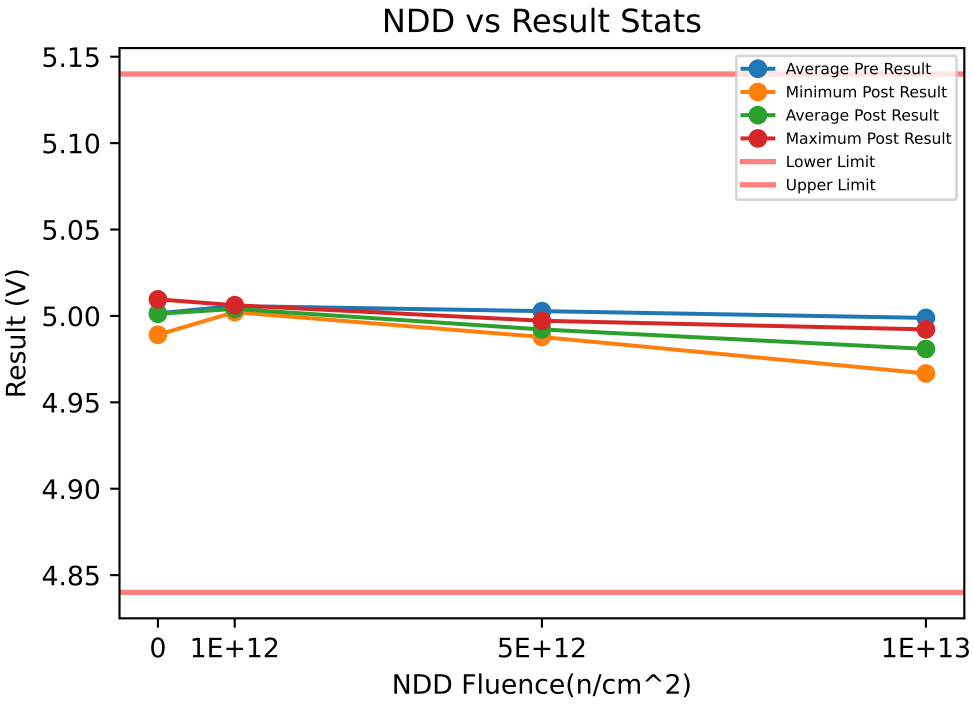
Test Results (Lower Limit = 90.0 (mA))

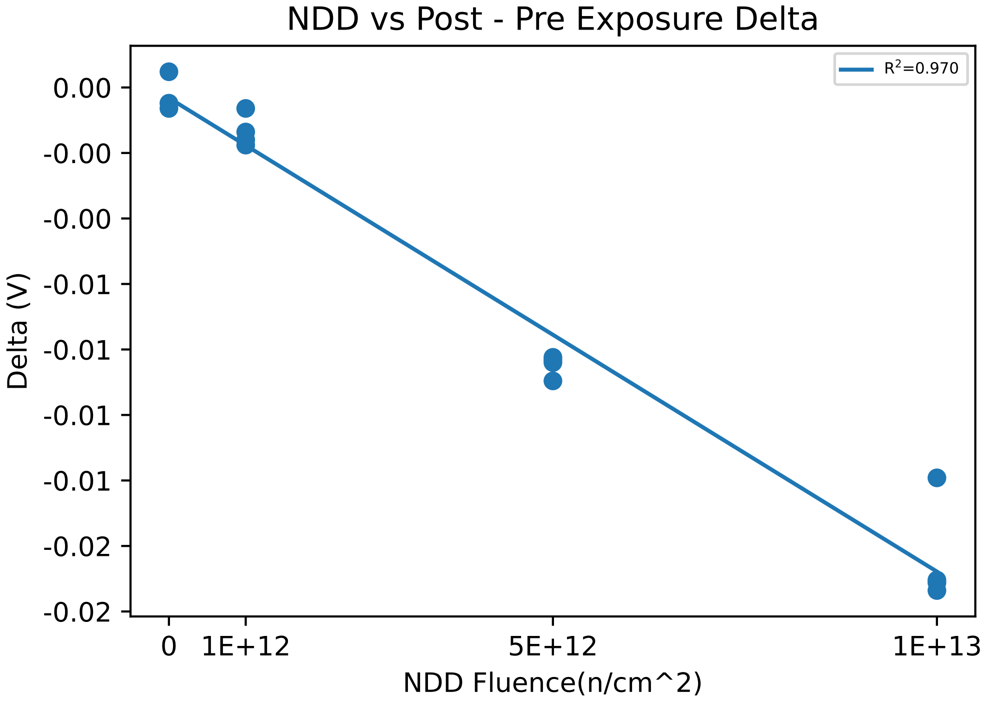
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	237.6	240.83	3.237
2	1e+12	NDD	238.6	241.72	3.1216
3	1e+12	NDD	241.79	232.76	-9.0358
4	1e+12	NDD	237.61	240.85	3.2381
5	5e+12	NDD	238.68	241.44	2.7619
6	5e+12	NDD	241.88	232.88	-8.9934
7	5e+12	NDD	237.61	240.89	3.2739
8	5e+12	NDD	238.62	241.8	3.1774
9	1e+13	NDD	241.81	232.82	-8.9937
10	1e+13	NDD	237.44	240.71	3.2696
11	1e+13	NDD	238.66	241.72	3.063
12	1e+13	NDD	241.88	232.86	-9.0256
13	0	CORRELATION	237.54	240.91	3.3732
14	0	CORRELATION	238.63	241.88	3.2497
15	0	CORRELATION	241.86	232.76	-9.0986

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	237.54	239.34	241.86	2.2481	232.76	238.52	241.88	5.0081	-9.0986	-0.82523	3.3732	7.1652
1e+12	237.6	238.9	241.79	1.9862	232.76	239.04	241.72	4.2077	-9.0358	0.14023	3.2381	6.1176
5e+12	237.61	239.2	241.88	1.8525	232.88	239.25	241.8	4.2623	-8.9934	0.05495	3.2739	6.0363
1e+13	237.44	239.95	241.88	2.2495	232.82	237.03	241.72	4.8534	-9.0256	-2.9217	3.2696	7.0303

Device Test: 15.8 VLDO|V_VLDO/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

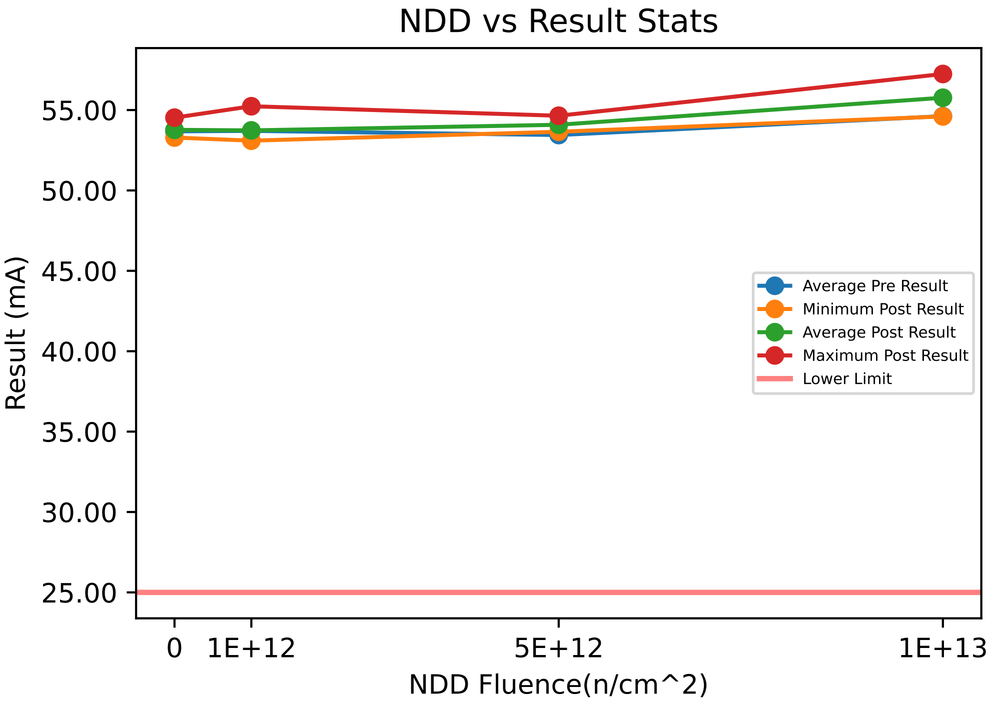
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

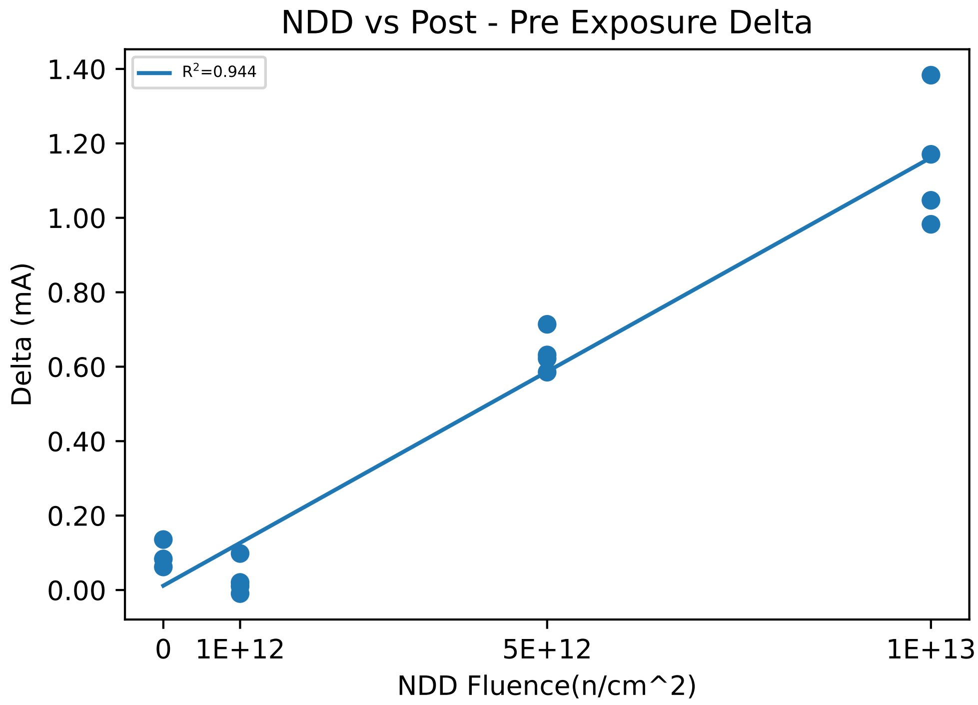
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.007	5.005	-0.002
2	1e+12	NDD	5.003	5.0022	-0.0008
3	1e+12	NDD	5.005	5.0028	-0.0022
4	1e+12	NDD	5.0079	5.0062	-0.0017
5	5e+12	NDD	5.0046	4.9934	-0.0112
6	5e+12	NDD	5.0077	4.9972	-0.0105
7	5e+12	NDD	5.0007	4.9903	-0.0104
8	5e+12	NDD	4.9981	4.9878	-0.0103
9	1e+13	NDD	4.9856	4.9667	-0.0189
10	1e+13	NDD	4.9957	4.9765	-0.0192
11	1e+13	NDD	5.0031	4.9882	-0.0149
12	1e+13	NDD	5.011	4.9922	-0.0188
13	0	CORRELATION	4.9897	4.9891	-0.0006
14	0	CORRELATION	5.0044	5.005	0.0006
15	0	CORRELATION	5.0104	5.0096	-0.0008

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9897	5.0015	5.0104	0.01065	4.9891	5.0012	5.0096	0.010757	-0.0008	-0.00026667	0.0006	0.00075719
1e+12	5.003	5.0057	5.0079	0.0021838	5.0022	5.004	5.0062	0.0018717	-0.0022	-0.001675	-0.0008	0.00061847
5e+12	4.9981	5.0028	5.0077	0.0042327	4.9878	4.9922	4.9972	0.0040582	-0.0112	-0.0106	-0.0103	0.00040825
1e+13	4.9856	4.9989	5.011	0.010819	4.9667	4.9809	4.9922	0.011576	-0.0192	-0.01795	-0.0149	0.0020404

Device Test: 15.9 VLDO|ILIM_VLDO/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_ILIM_5_PLUS_0P5





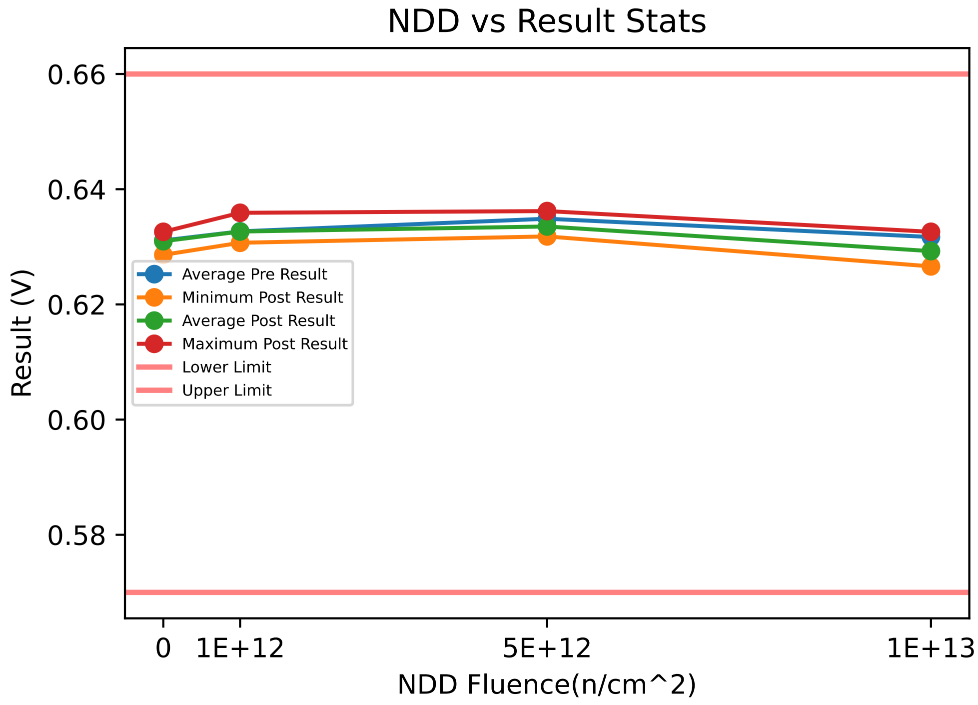
Test Results (Lower Limit = 25.0 (mA))

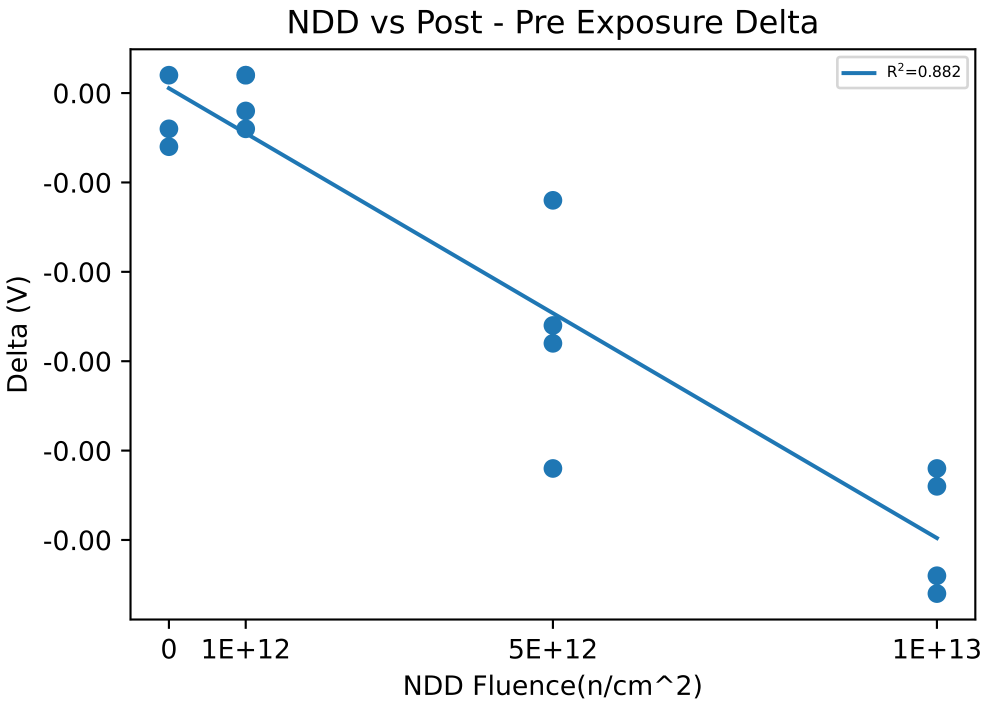
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	55.216	55.236	0.0204
2	1e+12	NDD	53.105	53.096	-0.0096
3	1e+12	NDD	53.085	53.095	0.0101
4	1e+12	NDD	53.413	53.511	0.0981
5	5e+12	NDD	53.472	54.186	0.7139
6	5e+12	NDD	53.269	53.854	0.5853
7	5e+12	NDD	53.027	53.649	0.6218
8	5e+12	NDD	54.015	54.646	0.6316
9	1e+13	NDD	54.982	56.029	1.047
10	1e+13	NDD	55.859	57.242	1.3832
11	1e+13	NDD	54.208	55.191	0.9826
12	1e+13	NDD	53.432	54.602	1.1706
13	0	CORRELATION	54.39	54.526	0.1356
14	0	CORRELATION	53.206	53.29	0.0835
15	0	CORRELATION	53.429	53.491	0.062

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.206	53.675	54.39	0.62928	53.29	53.769	54.526	0.66332	0.062	0.0937	0.1356	0.037845
1e+12	53.085	53.705	55.216	1.0183	53.095	53.734	55.236	1.02	-0.0096	0.02975	0.0981	0.047236
5e+12	53.027	53.446	54.015	0.42082	53.649	54.084	54.646	0.43553	0.5853	0.63815	0.7139	0.054288
1e+13	53.432	54.62	55.859	1.0402	54.602	55.766	57.242	1.1448	0.9826	1.1459	1.3832	0.17642

Device Test: 16.1 LEVEL|EN_RISE/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_RISE





Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

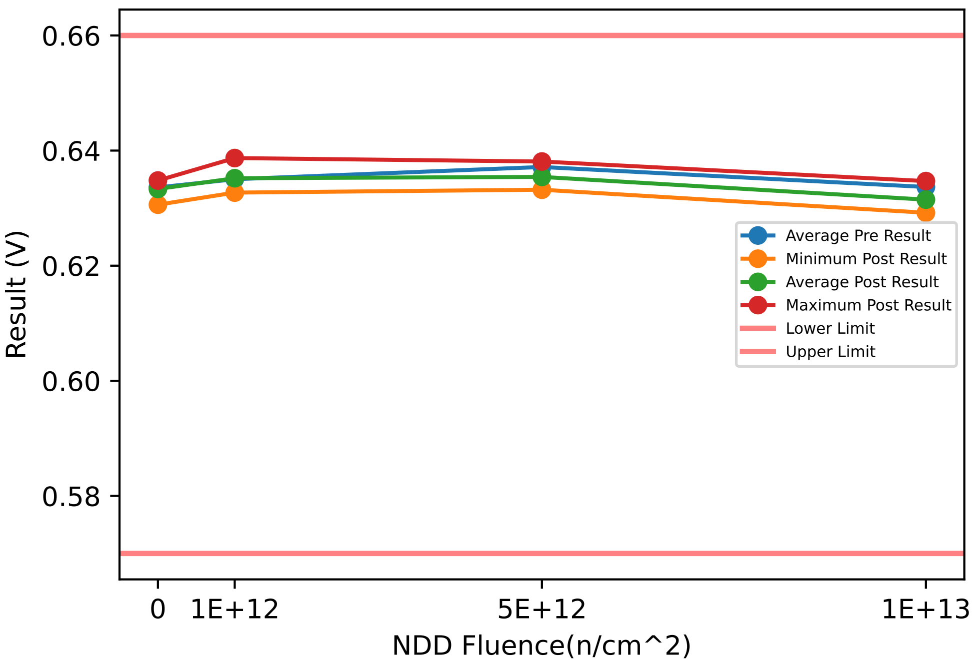
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6327	0.6326	-0.0001
2	1e+12	NDD	0.6313	0.6314	0.0001
3	1e+12	NDD	0.6306	0.6307	0.0001
4	1e+12	NDD	0.6361	0.6359	-0.0002
5	5e+12	NDD	0.634	0.6327	-0.0013
6	5e+12	NDD	0.6368	0.6362	-0.0006
7	5e+12	NDD	0.6332	0.6318	-0.0014
8	5e+12	NDD	0.6355	0.6334	-0.0021
9	1e+13	NDD	0.6328	0.6306	-0.0022
10	1e+13	NDD	0.6347	0.6326	-0.0021
11	1e+13	NDD	0.6293	0.6266	-0.0027
12	1e+13	NDD	0.63	0.6272	-0.0028
13	0	CORRELATION	0.632	0.6317	-0.0003
14	0	CORRELATION	0.6285	0.6286	0.0001
15	0	CORRELATION	0.6328	0.6326	-0.0002

Test Statistics (V)

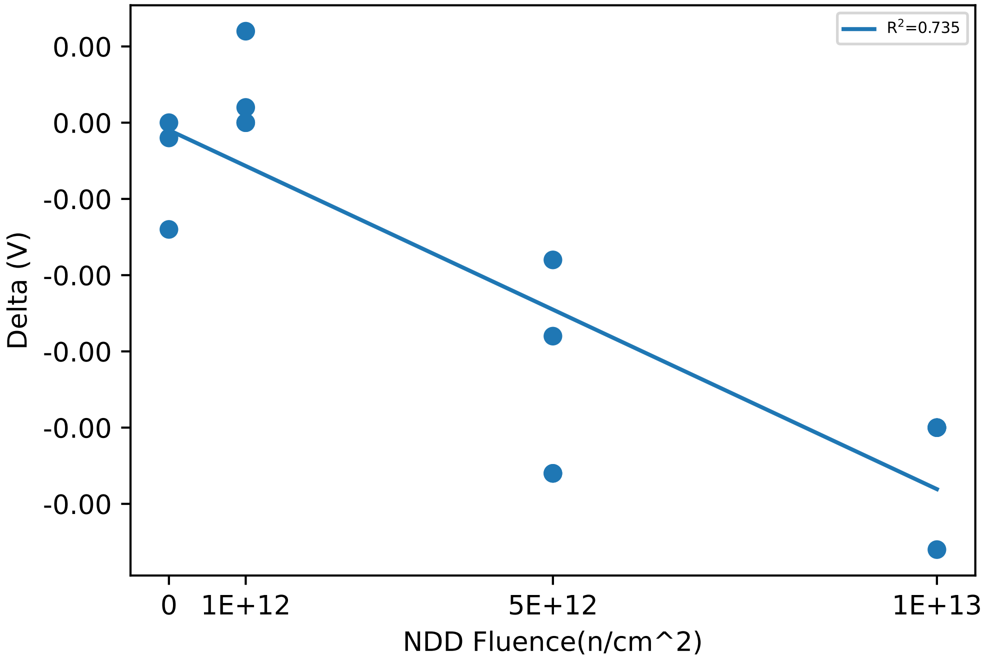
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6285	0.6311	0.6328	0.0022869	0.6286	0.63097	0.6326	0.0020984	-0.0003	-0.00013333	0.0001	0.00020817
1e+12	0.6306	0.63267	0.6361	0.0024446	0.6307	0.63265	0.6359	0.0023043	-0.0002	-2.5e-05	0.0001	0.00015
5e+12	0.6332	0.63487	0.6368	0.0015987	0.6318	0.63353	0.6362	0.0018998	-0.0021	-0.00135	-0.0006	0.00061373
1e+13	0.6293	0.6317	0.6347	0.0025073	0.6266	0.62925	0.6326	0.0028443	-0.0028	-0.00245	-0.0021	0.00035119

Device Test: 16.10 LEVEL|EN_RISE/EN/14/14/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



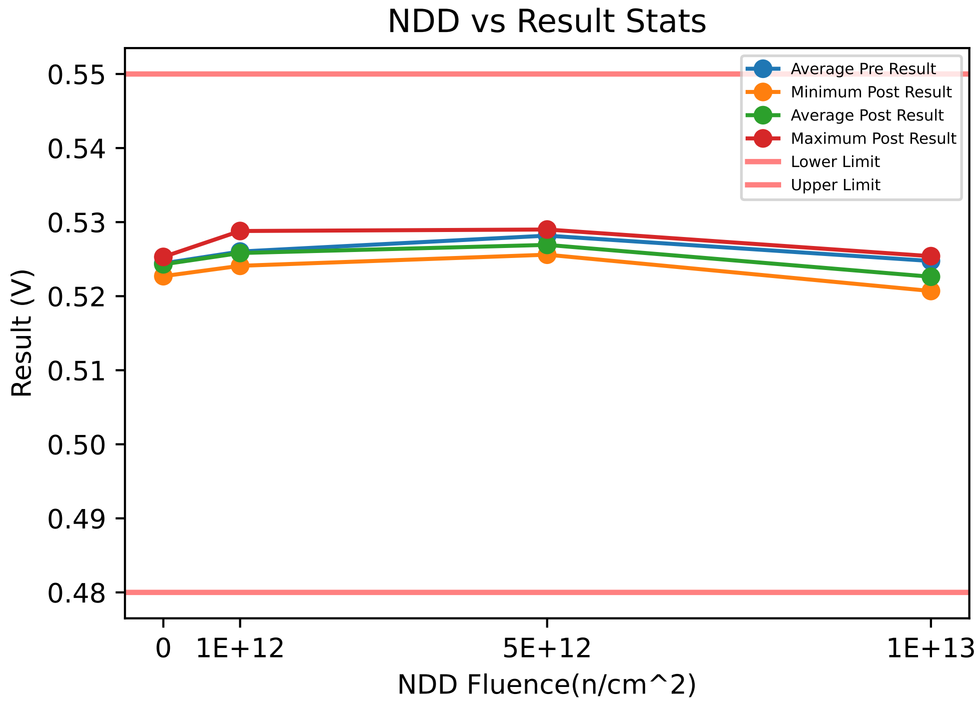
Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

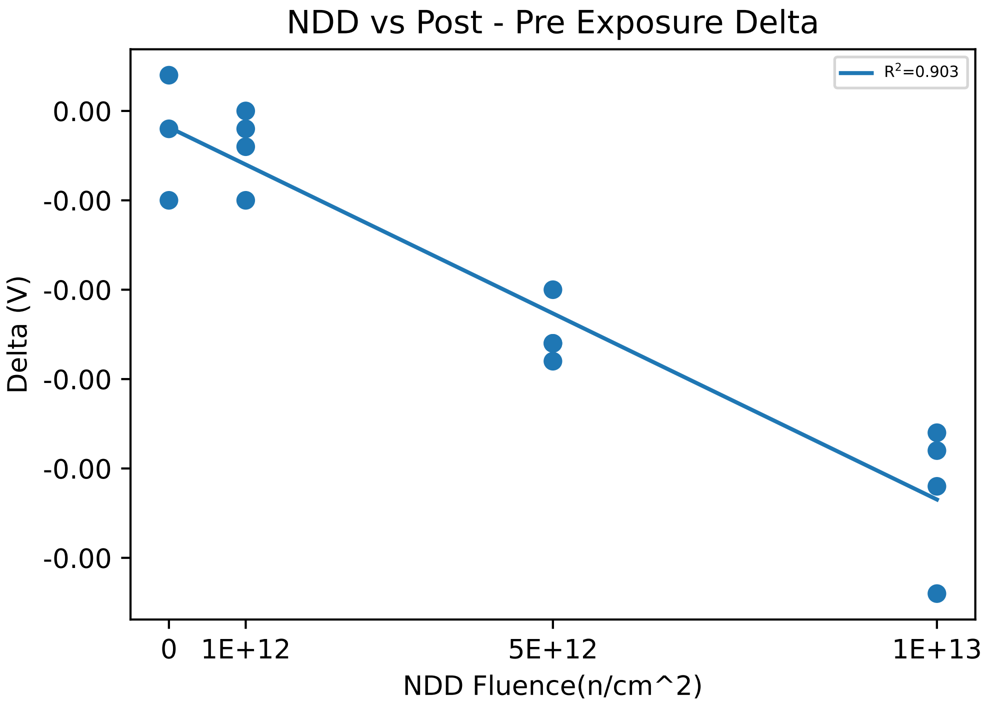
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6353	0.6353	0
2	1e+12	NDD	0.6335	0.6341	0.0006
3	1e+12	NDD	0.6326	0.6327	0.0001
4	1e+12	NDD	0.6387	0.6387	0
5	5e+12	NDD	0.6361	0.6352	-0.0009
6	5e+12	NDD	0.6395	0.6381	-0.0014
7	5e+12	NDD	0.6355	0.6332	-0.0023
8	5e+12	NDD	0.6375	0.6352	-0.0023
9	1e+13	NDD	0.6347	0.6327	-0.002
10	1e+13	NDD	0.6367	0.6347	-0.002
11	1e+13	NDD	0.6312	0.6292	-0.002
12	1e+13	NDD	0.6321	0.6293	-0.0028
13	0	CORRELATION	0.6347	0.6346	-0.0001
14	0	CORRELATION	0.6313	0.6306	-0.0007
15	0	CORRELATION	0.6348	0.6348	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6313	0.6336	0.6348	0.0019925	0.6306	0.63333	0.6348	0.0023692	-0.0007	-0.00026667	0	0.00037859
1e+12	0.6326	0.63502	0.6387	0.0026949	0.6327	0.6352	0.6387	0.0025639	0	0.000175	0.0006	0.00028723
5e+12	0.6355	0.63715	0.6395	0.0017767	0.6332	0.63543	0.6381	0.0020172	-0.0023	-0.001725	-0.0009	0.00069462
1e+13	0.6312	0.63367	0.6367	0.0025038	0.6292	0.63148	0.6347	0.0026961	-0.0028	-0.0022	-0.002	0.0004

Device Test: 16.11 LEVEL|EN_FALL/EN/14/14/0/0/5/500kHz//@V_EN_FALL





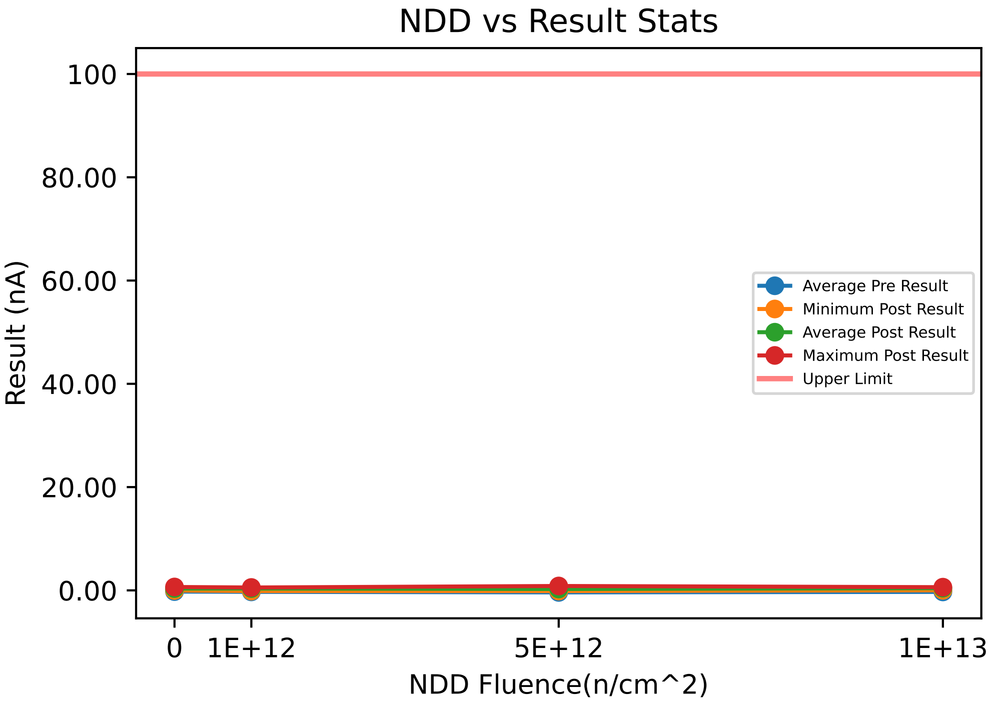
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

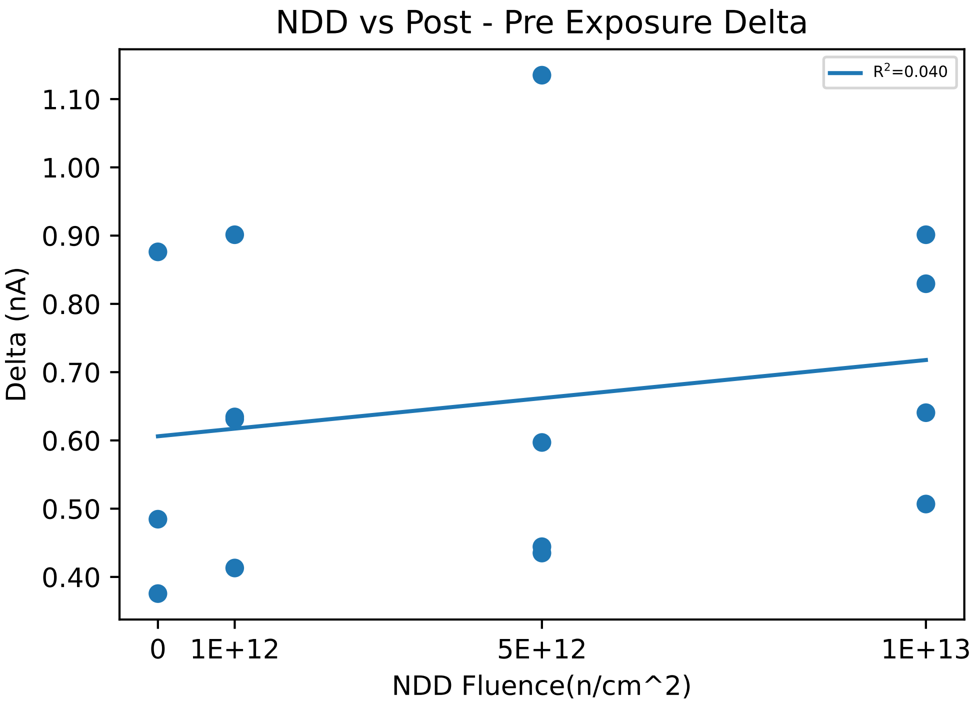
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5261	0.5256	-0.0005
2	1e+12	NDD	0.5249	0.5248	-0.0001
3	1e+12	NDD	0.5241	0.5241	0
4	1e+12	NDD	0.529	0.5288	-0.0002
5	5e+12	NDD	0.5282	0.5269	-0.0013
6	5e+12	NDD	0.5304	0.529	-0.0014
7	5e+12	NDD	0.5266	0.5256	-0.001
8	5e+12	NDD	0.5275	0.5262	-0.0013
9	1e+13	NDD	0.5254	0.5236	-0.0018
10	1e+13	NDD	0.5275	0.5254	-0.0021
11	1e+13	NDD	0.5227	0.5208	-0.0019
12	1e+13	NDD	0.5234	0.5207	-0.0027
13	0	CORRELATION	0.5254	0.5253	-0.0001
14	0	CORRELATION	0.5225	0.5227	0.0002
15	0	CORRELATION	0.5254	0.5249	-0.0005

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5225	0.52443	0.5254	0.0016743	0.5227	0.5243	0.5253	0.0014	-0.0005	-0.00013333	0.0002	0.00035119
1e+12	0.5241	0.52602	0.529	0.0021469	0.5241	0.52582	0.5288	0.0020759	-0.0005	-0.0002	0	0.00021602
5e+12	0.5266	0.52817	0.5304	0.0016215	0.5256	0.52692	0.529	0.0014818	-0.0014	-0.00125	-0.001	0.00017321
1e+13	0.5227	0.52475	0.5275	0.002161	0.5207	0.52263	0.5254	0.0022867	-0.0027	-0.002125	-0.0018	0.00040311

Device Test: 16.15 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK_1V





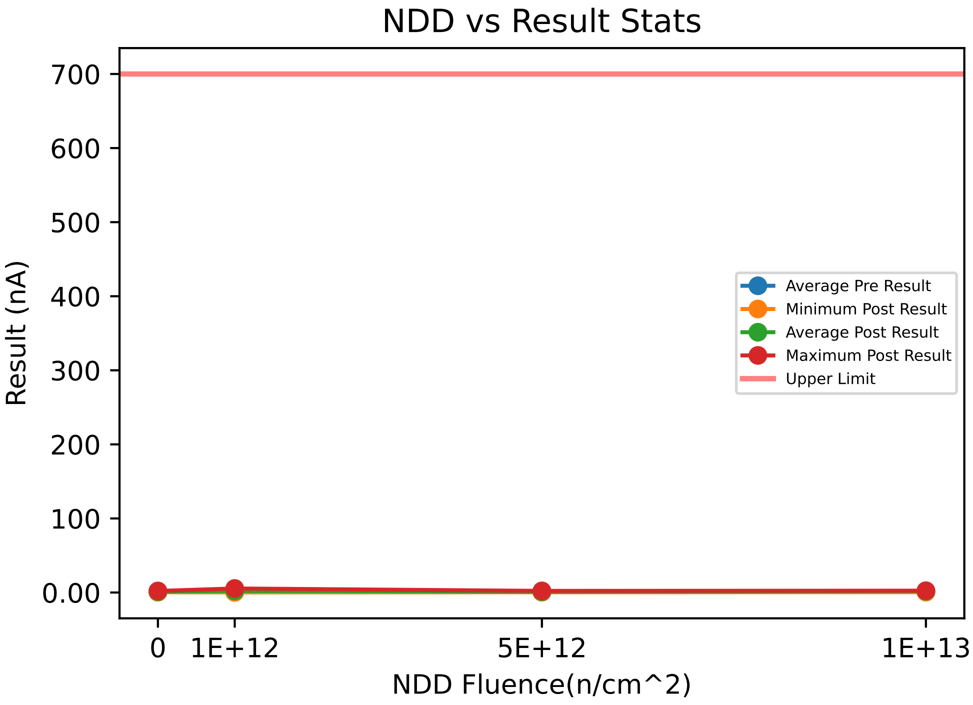
Test Results (Upper Limit = 100.0 (nA))

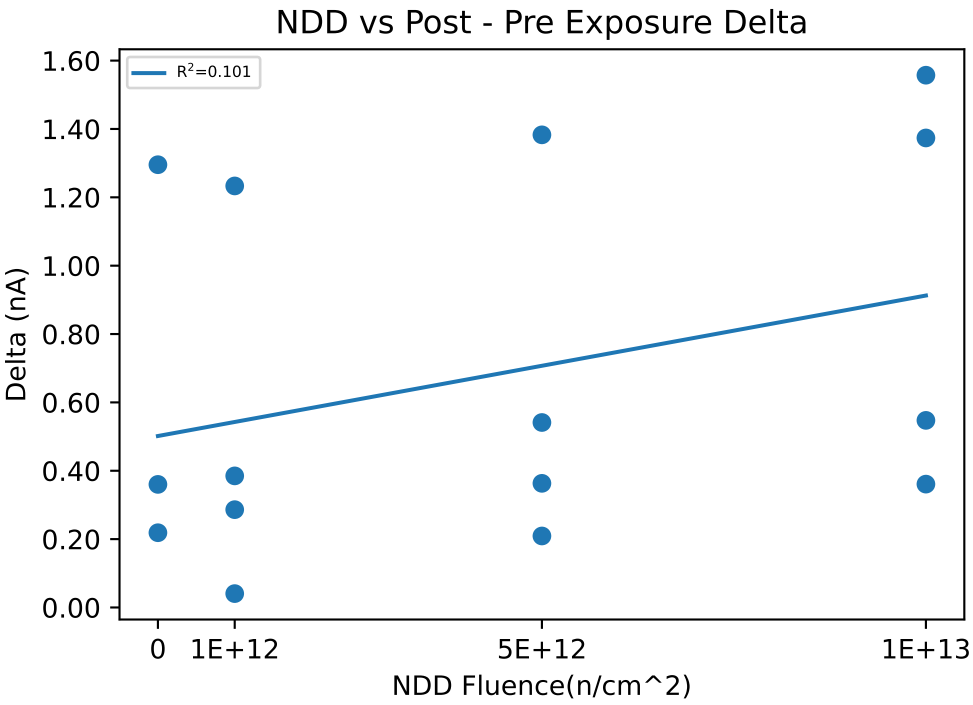
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.0995	0.5317	0.6312
2	1e+12	NDD	-0.5489	-0.1358	0.4131
3	1e+12	NDD	-0.3421	0.5592	0.9013
4	1e+12	NDD	-0.1682	0.4662	0.6344
5	5e+12	NDD	-0.5239	-0.0889	0.435
6	5e+12	NDD	-0.2859	0.8491	1.135
7	5e+12	NDD	-0.1838	0.4132	0.597
8	5e+12	NDD	-0.5801	-0.1358	0.4443
9	1e+13	NDD	-0.3545	0.5468	0.9013
10	1e+13	NDD	-0.1307	0.5099	0.6406
11	1e+13	NDD	-0.4989	0.0079	0.5068
12	1e+13	NDD	-0.211	0.6185	0.8295
13	0	CORRELATION	-0.087	0.3976	0.4846
14	0	CORRELATION	-0.4021	-0.0265	0.3756
15	0	CORRELATION	-0.2203	0.6559	0.8762

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4021	-0.23647	-0.087	0.15817	-0.0265	0.34233	0.6559	0.34454	0.3756	0.5788	0.8762	0.26326
1e+12	-0.5489	-0.28968	-0.0995	0.20072	-0.1358	0.35533	0.5592	0.32973	0.4131	0.645	0.9013	0.19981
5e+12	-0.5801	-0.39343	-0.1838	0.18919	-0.1358	0.2594	0.8491	0.46508	0.435	0.65282	1.135	0.32992
1e+13	-0.4989	-0.29878	-0.1307	0.16239	0.0079	0.42078	0.6185	0.27892	0.5068	0.71955	0.9013	0.17946

Device Test: 16.16 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK





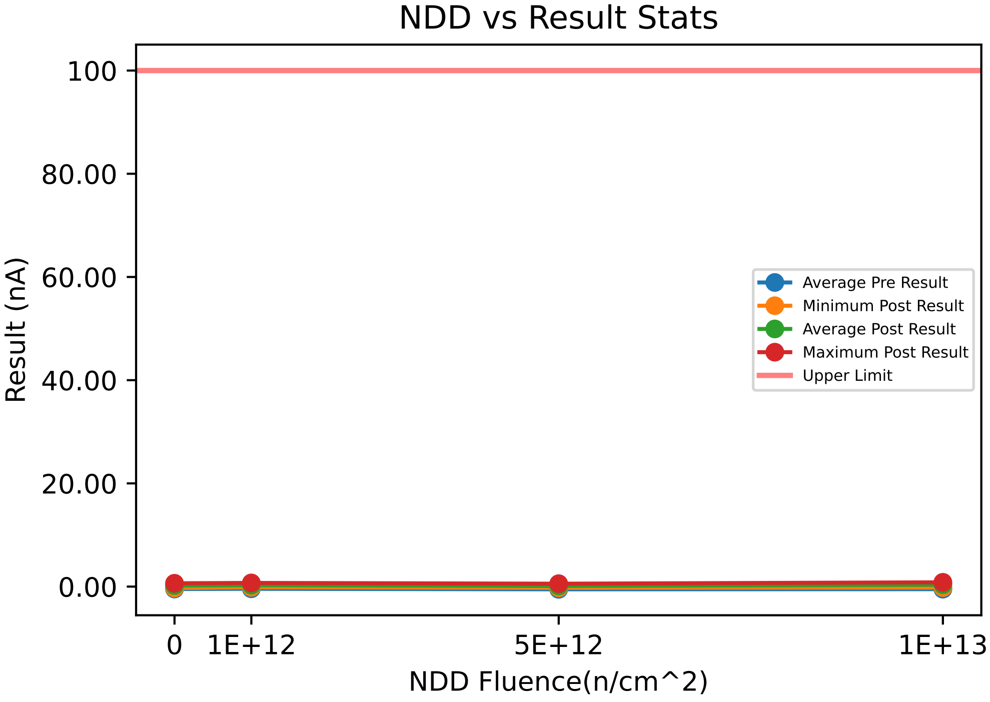
Test Results (Upper Limit = 700.0 (nA))

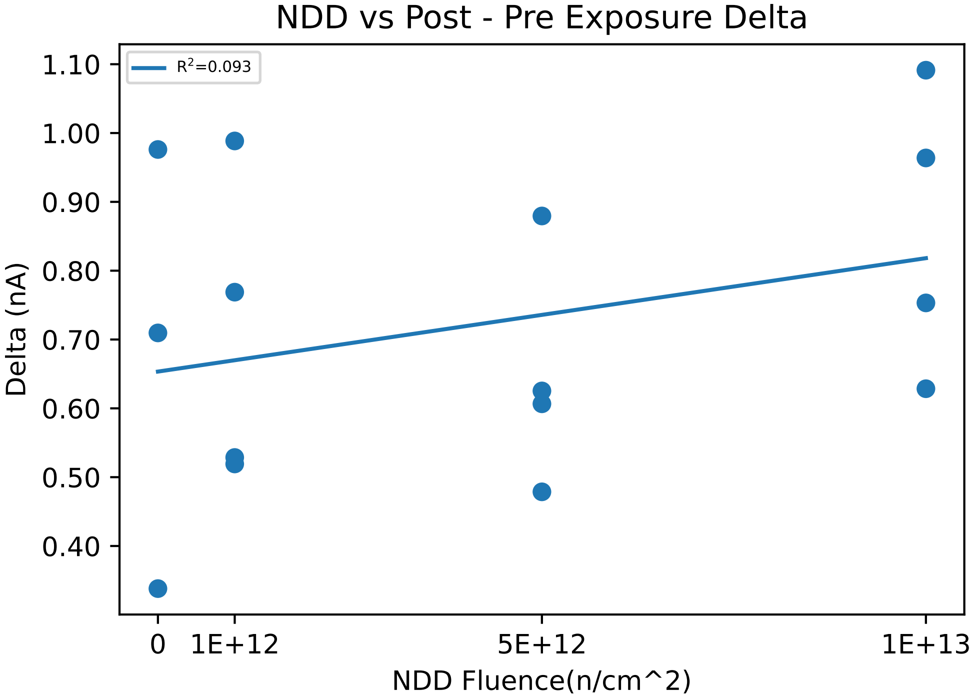
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.1669	5.4531	0.2862
2	1e+12	NDD	-0.2148	0.1702	0.385
3	1e+12	NDD	0.7192	1.9525	1.2333
4	1e+12	NDD	1.0899	1.1305	0.0406
5	5e+12	NDD	0.0568	0.42	0.3632
6	5e+12	NDD	0.8097	2.1925	1.3828
7	5e+12	NDD	0.8308	1.04	0.2092
8	5e+12	NDD	0.5063	1.0475	0.5412
9	1e+13	NDD	0.61	1.9837	1.3737
10	1e+13	NDD	2.1013	2.4622	0.3609
11	1e+13	NDD	-0.065	0.4824	0.5474
12	1e+13	NDD	0.7941	2.3514	1.5573
13	0	CORRELATION	0.8058	1.0245	0.2187
14	0	CORRELATION	0.0693	0.4294	0.3601
15	0	CORRELATION	0.816	2.1114	1.2954

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0693	0.5637	0.816	0.42819	0.4294	1.1884	2.1114	0.8529	0.2187	0.62473	1.2954	0.5851
1e+12	-0.2148	1.6903	5.1669	2.3819	0.1702	2.1766	5.4531	2.3026	0.0406	0.48627	1.2333	0.51864
5e+12	0.0568	0.5509	0.8308	0.36122	0.42	1.175	2.1925	0.73933	0.2092	0.6241	1.3828	0.52368
1e+13	-0.065	0.8601	2.1013	0.90614	0.4824	1.8199	2.4622	0.91484	0.3609	0.95982	1.5573	0.5936

Device Test: 16.17 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK_1V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

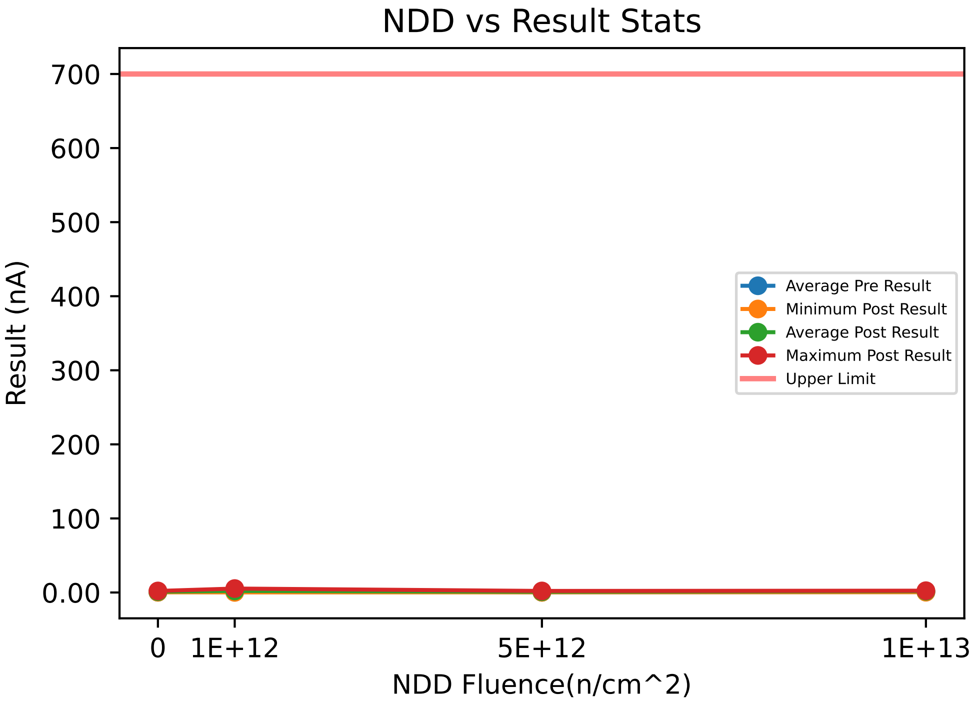
Test Results (Upper Limit = 100.0 (nA))

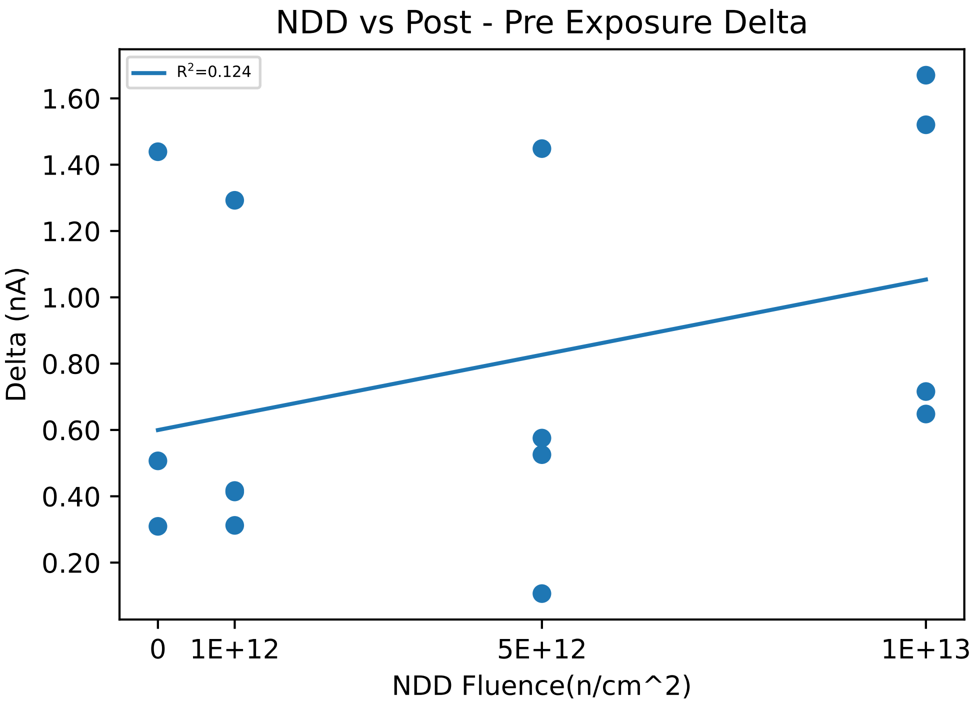
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.3368	0.1824	0.5192
2	1e+12	NDD	-0.6612	-0.1326	0.5286
3	1e+12	NDD	-0.2765	0.712	0.9885
4	1e+12	NDD	-0.4211	0.3477	0.7688
5	5e+12	NDD	-0.7081	-0.2294	0.4787
6	5e+12	NDD	-0.3171	0.5624	0.8795
7	5e+12	NDD	-0.4211	0.2042	0.6253
8	5e+12	NDD	-0.6612	-0.0546	0.6066
9	1e+13	NDD	-0.2609	0.8304	1.0913
10	1e+13	NDD	-0.4741	0.2791	0.7532
11	1e+13	NDD	-0.8111	-0.1826	0.6285
12	1e+13	NDD	-0.4388	0.525	0.9638
13	0	CORRELATION	-0.4648	0.2448	0.7096
14	0	CORRELATION	-0.6144	-0.2763	0.3381
15	0	CORRELATION	-0.3327	0.6434	0.9761

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6144	-0.47063	-0.3327	0.14094	-0.2763	0.20397	0.6434	0.46121	0.3381	0.6746	0.9761	0.32044
1e+12	-0.6612	-0.4239	-0.2765	0.16895	-0.1326	0.27738	0.712	0.35164	0.5192	0.70127	0.9885	0.22363
5e+12	-0.7081	-0.52687	-0.3171	0.18804	-0.2294	0.12065	0.5624	0.34418	0.4787	0.64752	0.8795	0.16781
1e+13	-0.8111	-0.49623	-0.2609	0.22972	-0.1826	0.36298	0.8304	0.42795	0.6285	0.8592	1.0913	0.20758

Device Test: 16.18 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK





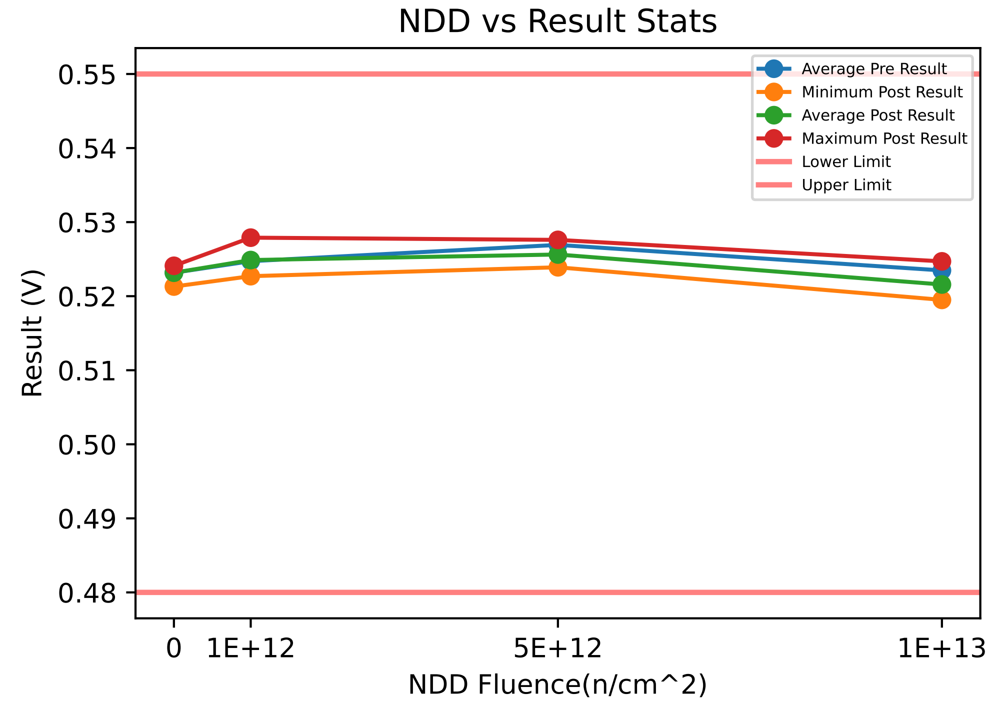
Test Results (Upper Limit = 700.0 (nA))

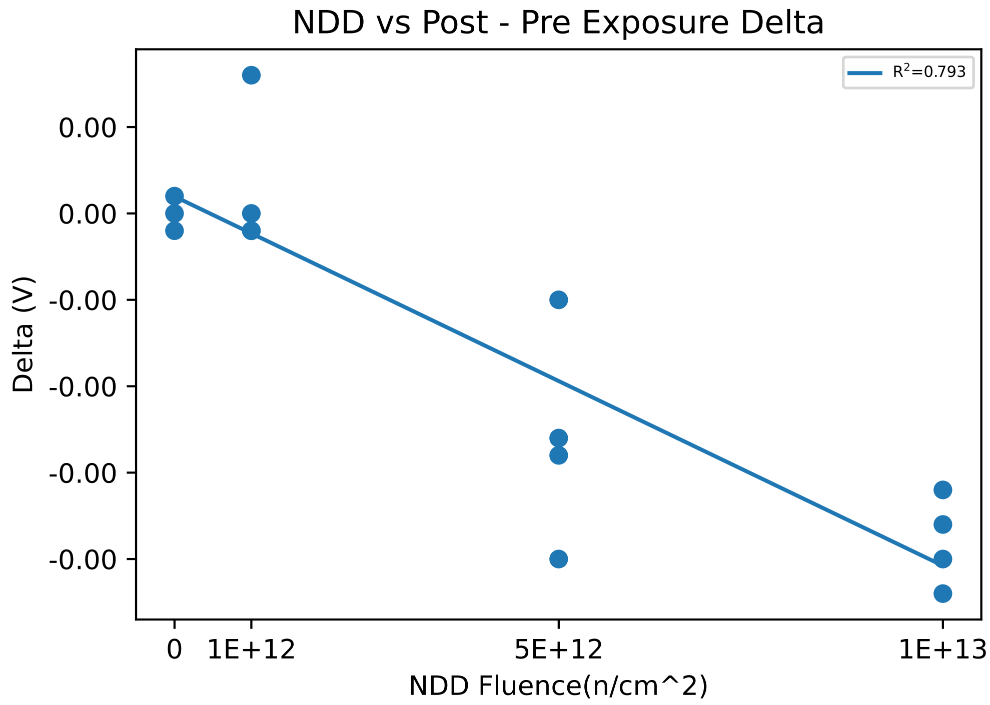
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.9047	5.3221	0.4174
2	1e+12	NDD	-0.2897	0.1234	0.4131
3	1e+12	NDD	0.5944	1.887	1.2926
4	1e+12	NDD	0.7996	1.1118	0.3122
5	5e+12	NDD	-0.3085	0.217	0.5255
6	5e+12	NDD	0.6318	2.0803	1.4485
7	5e+12	NDD	0.7215	0.828	0.1065
8	5e+12	NDD	0.2535	0.829	0.5755
9	1e+13	NDD	0.4882	2.0086	1.5204
10	1e+13	NDD	1.7798	2.4279	0.6481
11	1e+13	NDD	-0.3334	0.3825	0.7159
12	1e+13	NDD	0.5569	2.2268	1.6699
13	0	CORRELATION	0.606	0.9153	0.3093
14	0	CORRELATION	-0.2242	0.2826	0.5068
15	0	CORRELATION	0.6287	2.0678	1.4391

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2242	0.33683	0.6287	0.486	0.2826	1.0886	2.0678	0.90512	0.3093	0.75173	1.4391	0.60341
1e+12	-0.2897	1.5023	4.9047	2.317	0.1234	2.1111	5.3221	2.2591	0.3122	0.60882	1.2926	0.45843
5e+12	-0.3085	0.32458	0.7215	0.46825	0.217	0.98857	2.0803	0.78282	0.1065	0.664	1.4485	0.5637
1e+13	-0.3334	0.62288	1.7798	0.87091	0.3825	1.7614	2.4279	0.93511	0.6481	1.1386	1.6699	0.53145

Device Test: 16.2 LEVEL|EN_FALL/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_FALL





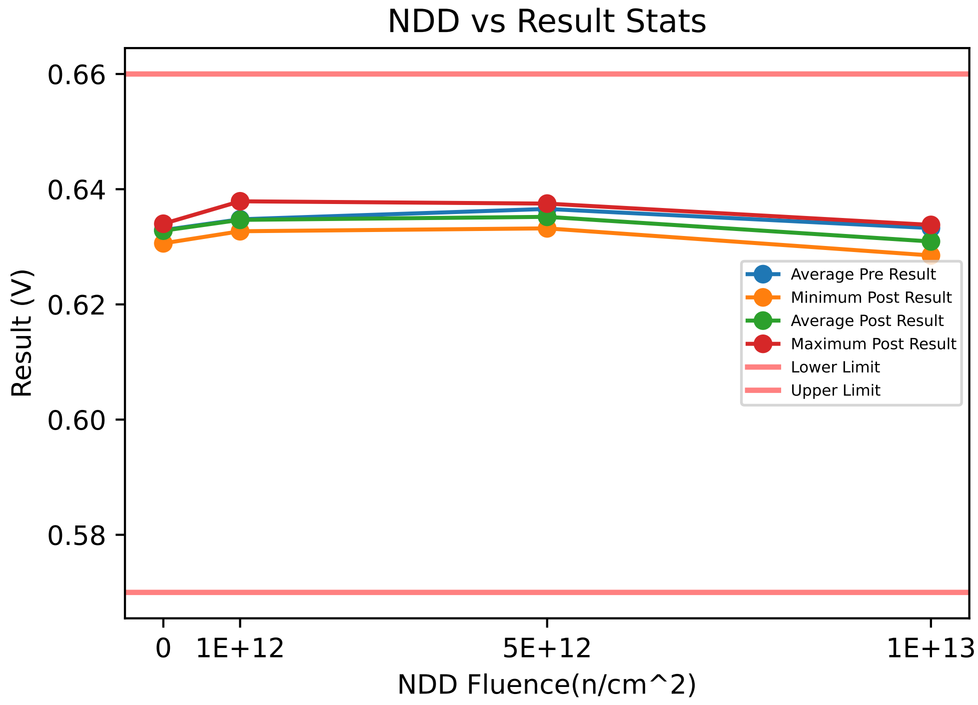
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

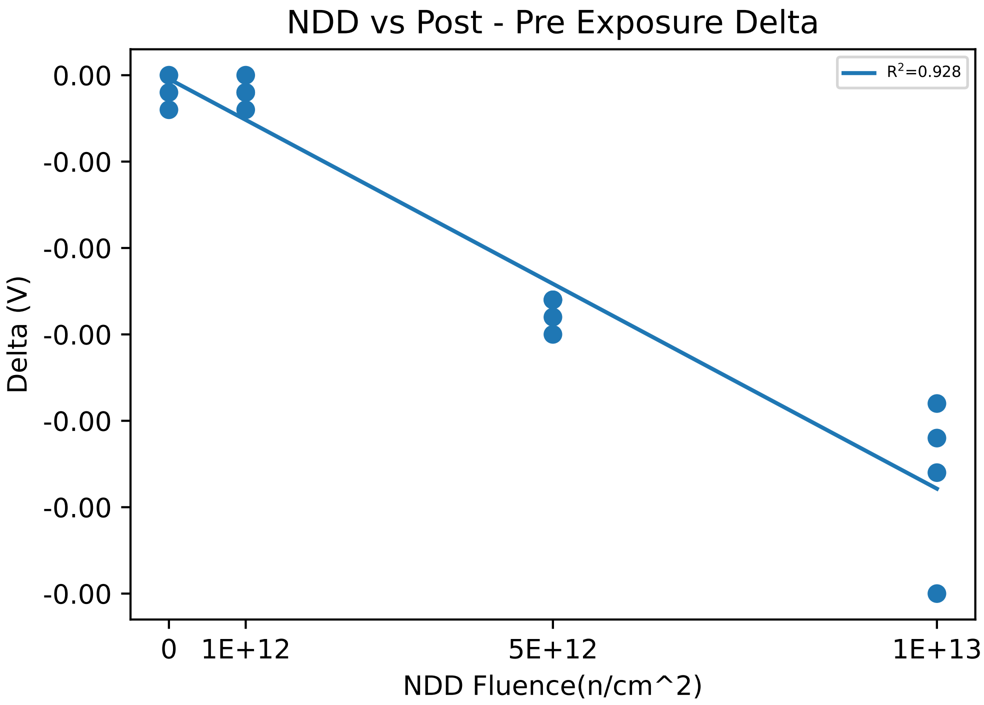
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5248	0.5247	-0.0001
2	1e+12	NDD	0.5234	0.5242	0.0008
3	1e+12	NDD	0.5227	0.5227	0
4	1e+12	NDD	0.528	0.5279	-0.0001
5	5e+12	NDD	0.5267	0.5262	-0.0005
6	5e+12	NDD	0.5289	0.5276	-0.0013
7	5e+12	NDD	0.5253	0.5239	-0.0014
8	5e+12	NDD	0.5268	0.5248	-0.002
9	1e+13	NDD	0.5241	0.5221	-0.002
10	1e+13	NDD	0.5263	0.5247	-0.0016
11	1e+13	NDD	0.5213	0.5195	-0.0018
12	1e+13	NDD	0.5222	0.52	-0.0022
13	0	CORRELATION	0.524	0.5241	0.0001
14	0	CORRELATION	0.5214	0.5213	-0.0001
15	0	CORRELATION	0.5241	0.5241	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5214	0.52317	0.5241	0.0015308	0.5213	0.52317	0.5241	0.0016166	-0.0001	0	0.0001	0.0001
1e+12	0.5227	0.52472	0.528	0.0023514	0.5227	0.52487	0.5279	0.0021884	-0.0001	0.00015	0.0008	0.00043589
5e+12	0.5253	0.52692	0.5289	0.0014841	0.5239	0.52563	0.5276	0.0016215	-0.002	-0.0013	-0.0005	0.00061644
1e+13	0.5213	0.52348	0.5263	0.0022157	0.5195	0.52158	0.5247	0.0023684	-0.0022	-0.0019	-0.0016	0.0002582

Device Test: 16.4 LEVEL|EN_RISE/EN/5/5/0/0/5/500kHz//@V_EN_RISE


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

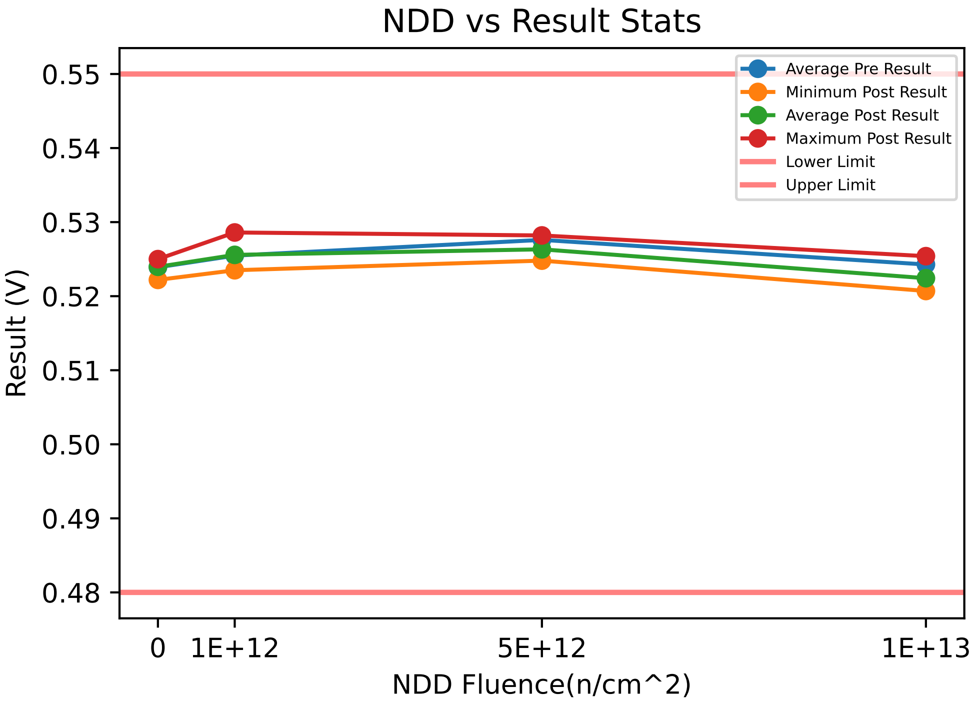
Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

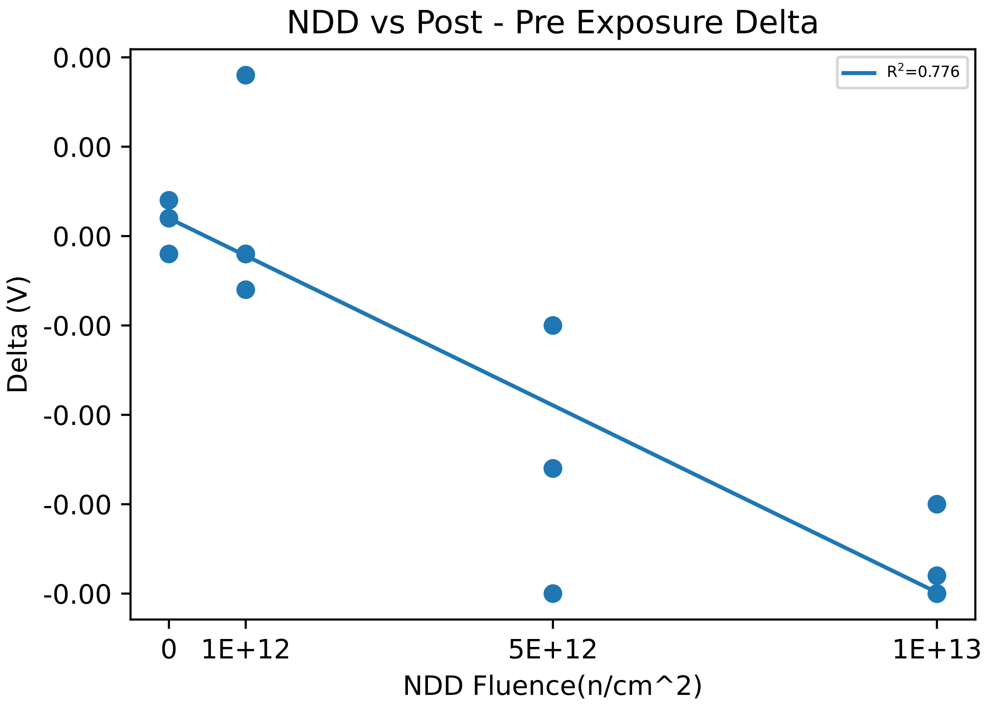
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6347	0.6347	0
2	1e+12	NDD	0.6335	0.6334	-0.0001
3	1e+12	NDD	0.6328	0.6327	-0.0001
4	1e+12	NDD	0.6381	0.6379	-0.0002
5	5e+12	NDD	0.6362	0.6347	-0.0015
6	5e+12	NDD	0.6388	0.6375	-0.0013
7	5e+12	NDD	0.6346	0.6332	-0.0014
8	5e+12	NDD	0.6367	0.6354	-0.0013
9	1e+13	NDD	0.6348	0.6327	-0.0021
10	1e+13	NDD	0.6361	0.6338	-0.0023
11	1e+13	NDD	0.6306	0.6287	-0.0019
12	1e+13	NDD	0.6315	0.6285	-0.003
13	0	CORRELATION	0.634	0.6338	-0.0002
14	0	CORRELATION	0.6306	0.6306	0
15	0	CORRELATION	0.6341	0.634	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6306	0.6329	0.6341	0.0019925	0.6306	0.6328	0.634	0.0019079	-0.0002	-0.0001	0	0.0001
1e+12	0.6328	0.63477	0.6381	0.0023514	0.6327	0.63467	0.6379	0.0023042	-0.0002	-0.0001	0	8.165e-05
5e+12	0.6346	0.63658	0.6388	0.0017328	0.6332	0.6352	0.6375	0.001787	-0.0015	-0.001375	-0.0013	9.5743e-05
1e+13	0.6306	0.63325	0.6361	0.0026211	0.6285	0.63092	0.6338	0.0027232	-0.003	-0.002325	-0.0019	0.00047871

Device Test: 16.5 LEVEL|EN_FALL/EN/5/5/0/0/5/500kHz//@V_EN_FALL





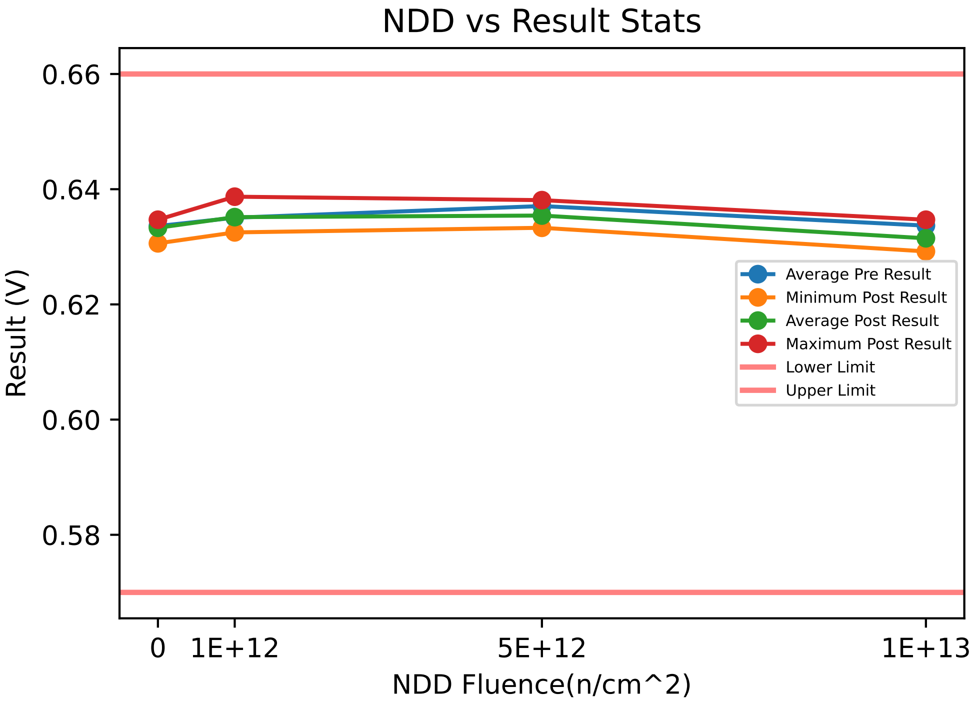
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

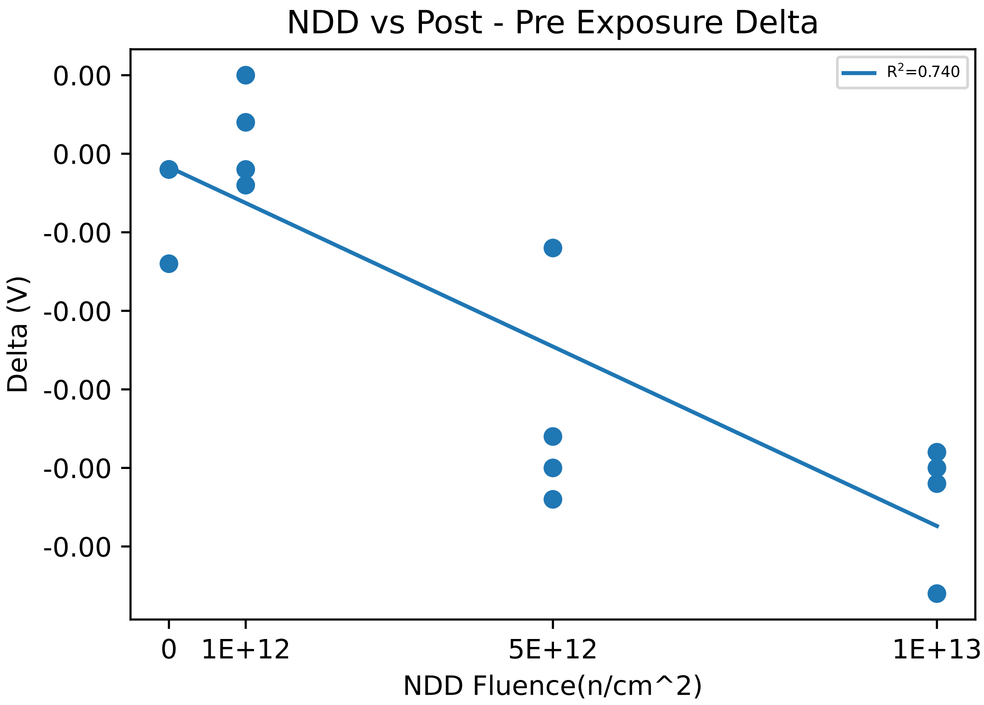
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5254	0.5253	-0.0001
2	1e+12	NDD	0.524	0.5249	0.0009
3	1e+12	NDD	0.5236	0.5235	-0.0001
4	1e+12	NDD	0.5289	0.5286	-0.0003
5	5e+12	NDD	0.5274	0.5269	-0.0005
6	5e+12	NDD	0.5295	0.5282	-0.0013
7	5e+12	NDD	0.5261	0.5248	-0.0013
8	5e+12	NDD	0.5274	0.5254	-0.002
9	1e+13	NDD	0.5248	0.5229	-0.0019
10	1e+13	NDD	0.5274	0.5254	-0.002
11	1e+13	NDD	0.5222	0.5207	-0.0015
12	1e+13	NDD	0.5227	0.5207	-0.002
13	0	CORRELATION	0.5248	0.5247	-0.0001
14	0	CORRELATION	0.522	0.5222	0.0002
15	0	CORRELATION	0.5249	0.525	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.522	0.5239	0.5249	0.0016462	0.5222	0.52397	0.525	0.0015373	-0.0001	6.6667e-05	0.0002	0.00015275
1e+12	0.5236	0.52548	0.5289	0.0024102	0.5235	0.52558	0.5286	0.0021593	-0.0003	0.0001	0.0009	0.0005416
5e+12	0.5261	0.5276	0.5295	0.0014071	0.5248	0.52633	0.5282	0.0015305	-0.002	-0.001275	-0.0005	0.00061305
1e+13	0.5222	0.52428	0.5274	0.0023684	0.5207	0.52243	0.5254	0.0022381	-0.002	-0.00185	-0.0015	0.00023805

Device Test: 16.7 LEVEL|EN_RISE/EN/12/12/0/0/5/500kHz//@V_EN_RISE


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

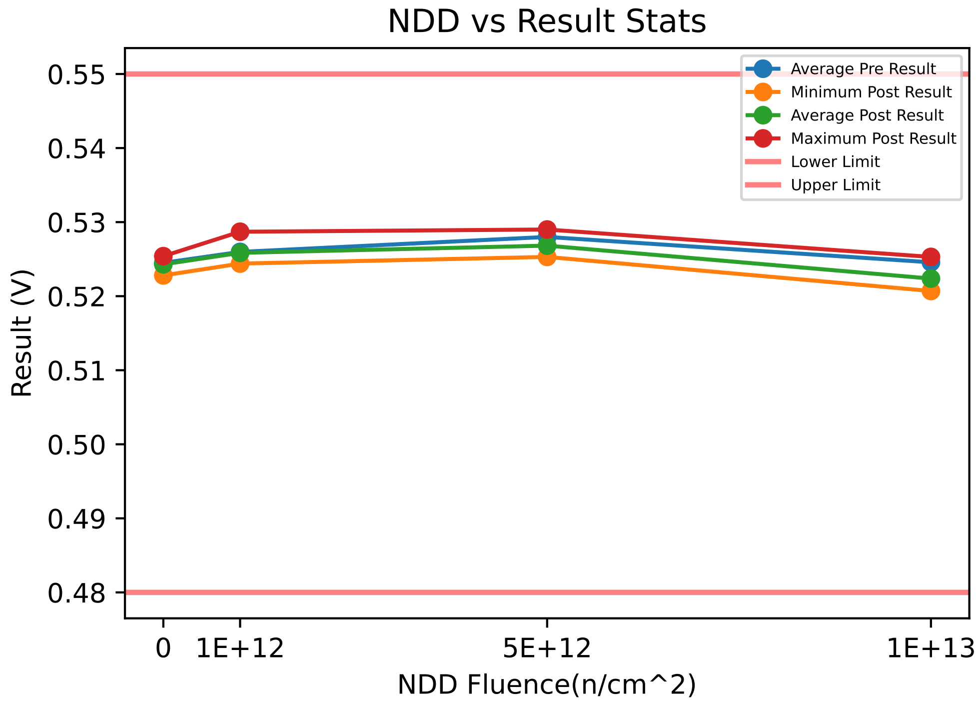
Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

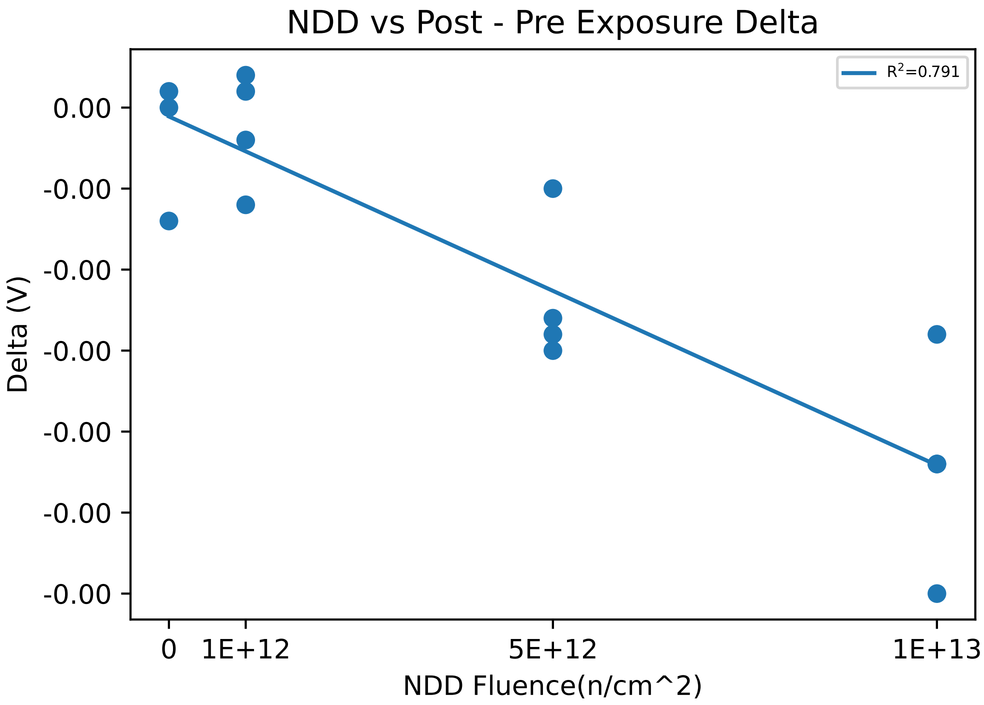
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6347	0.6352	0.0005
2	1e+12	NDD	0.634	0.6342	0.0002
3	1e+12	NDD	0.6327	0.6325	-0.0002
4	1e+12	NDD	0.6388	0.6387	-0.0001
5	5e+12	NDD	0.6367	0.6349	-0.0018
6	5e+12	NDD	0.6387	0.6381	-0.0006
7	5e+12	NDD	0.6353	0.6333	-0.002
8	5e+12	NDD	0.6376	0.6354	-0.0022
9	1e+13	NDD	0.6347	0.6328	-0.0019
10	1e+13	NDD	0.6367	0.6347	-0.002
11	1e+13	NDD	0.6313	0.6292	-0.0021
12	1e+13	NDD	0.632	0.6292	-0.0028
13	0	CORRELATION	0.6347	0.6346	-0.0001
14	0	CORRELATION	0.6313	0.6306	-0.0007
15	0	CORRELATION	0.6348	0.6347	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6313	0.6336	0.6348	0.0019925	0.6306	0.6333	0.6347	0.0023388	-0.0007	-0.0003	-0.0001	0.00034641
1e+12	0.6327	0.63505	0.6388	0.0026338	0.6325	0.63515	0.6387	0.002616	-0.0002	0.0001	0.0005	0.00031623
5e+12	0.6353	0.63708	0.6387	0.0014385	0.6333	0.63543	0.6381	0.0019956	-0.0022	-0.00165	-0.0006	0.0007188
1e+13	0.6313	0.63367	0.6367	0.0024932	0.6292	0.63148	0.6347	0.0027391	-0.0028	-0.0022	-0.0019	0.00040825

Device Test: 16.8 LEVEL|EN_FALL/EN/12/12/0/0/5/500kHz//@V_EN_FALL





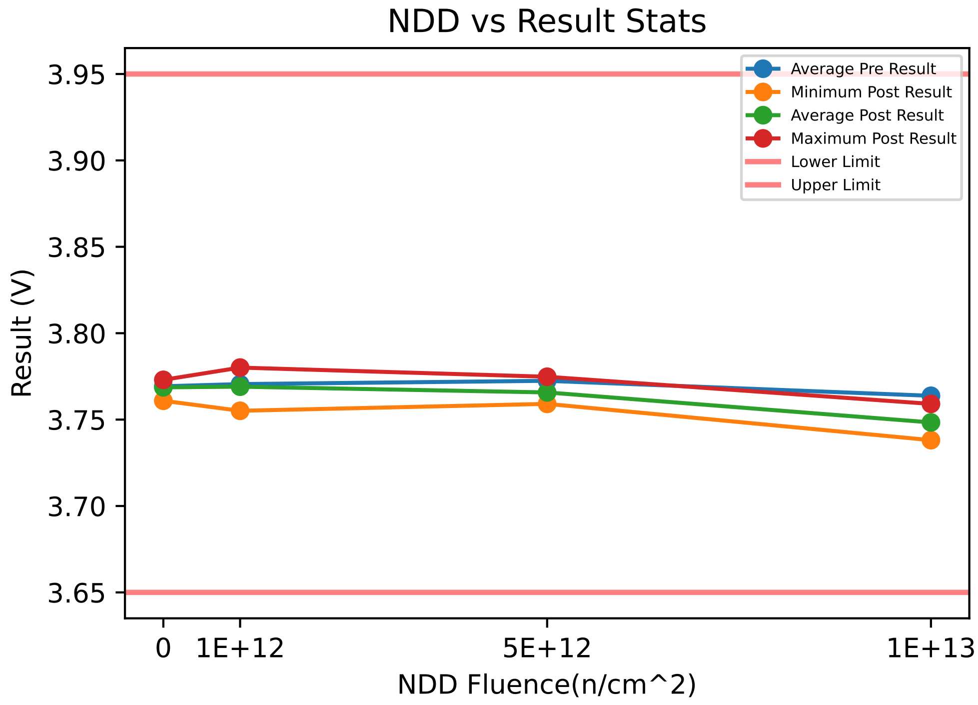
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

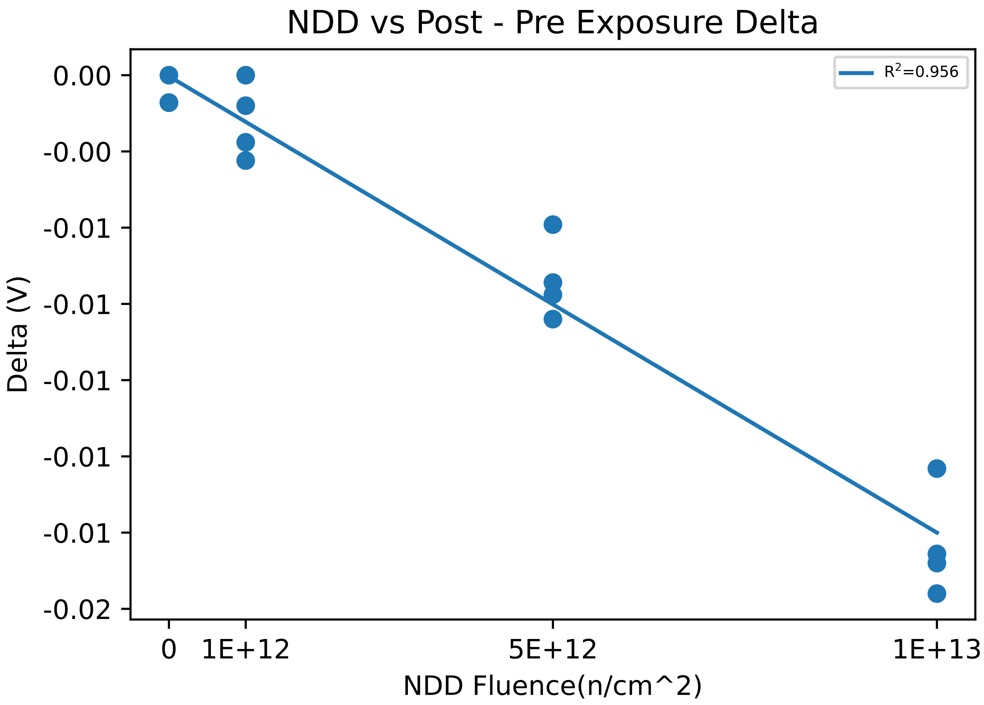
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.526	0.5254	-0.0006
2	1e+12	NDD	0.5247	0.5249	0.0002
3	1e+12	NDD	0.5243	0.5244	0.0001
4	1e+12	NDD	0.5289	0.5287	-0.0002
5	5e+12	NDD	0.5282	0.5268	-0.0014
6	5e+12	NDD	0.5295	0.529	-0.0005
7	5e+12	NDD	0.5268	0.5253	-0.0015
8	5e+12	NDD	0.5275	0.5262	-0.0013
9	1e+13	NDD	0.5249	0.5227	-0.0022
10	1e+13	NDD	0.5275	0.5253	-0.0022
11	1e+13	NDD	0.5222	0.5208	-0.0014
12	1e+13	NDD	0.5237	0.5207	-0.003
13	0	CORRELATION	0.5254	0.5254	0
14	0	CORRELATION	0.5227	0.5228	0.0001
15	0	CORRELATION	0.5254	0.5247	-0.0007

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5227	0.5245	0.5254	0.0015588	0.5228	0.5243	0.5254	0.0013454	-0.0007	-0.0002	0.0001	0.00043589
1e+12	0.5243	0.52598	0.5289	0.0020807	0.5244	0.52585	0.5287	0.0019434	-0.0006	-0.000125	0.0002	0.0003594
5e+12	0.5268	0.528	0.5295	0.0011518	0.5253	0.52682	0.529	0.0015756	-0.0015	-0.001175	-0.0005	0.00045735
1e+13	0.5222	0.52458	0.5275	0.0022411	0.5207	0.52238	0.5253	0.0021562	-0.003	-0.0022	-0.0014	0.0006532

Device Test: 17.1 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_RISE





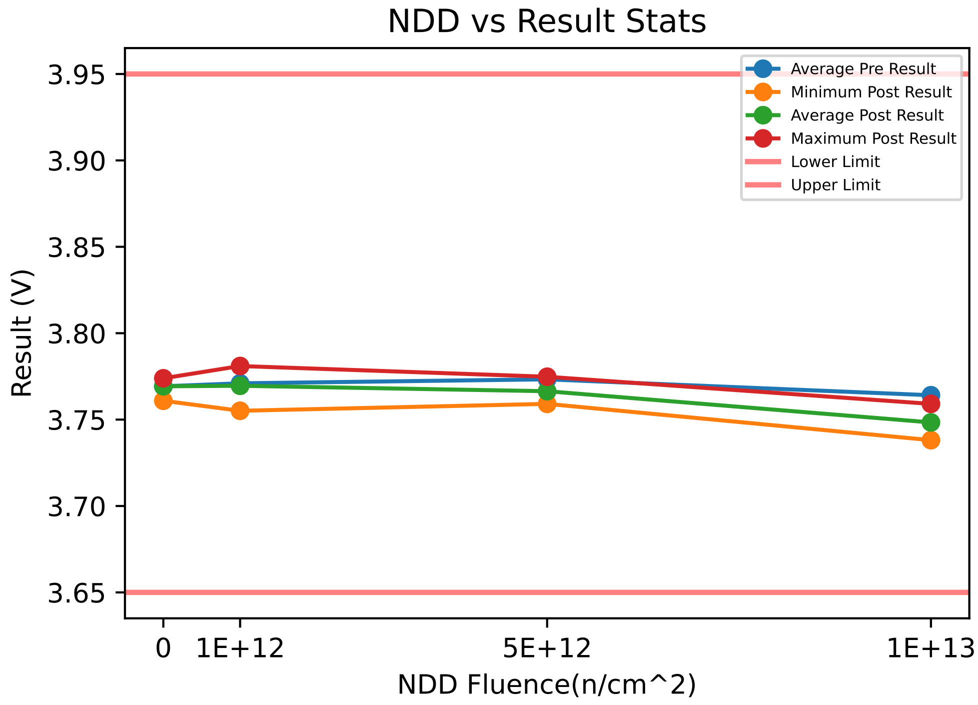
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

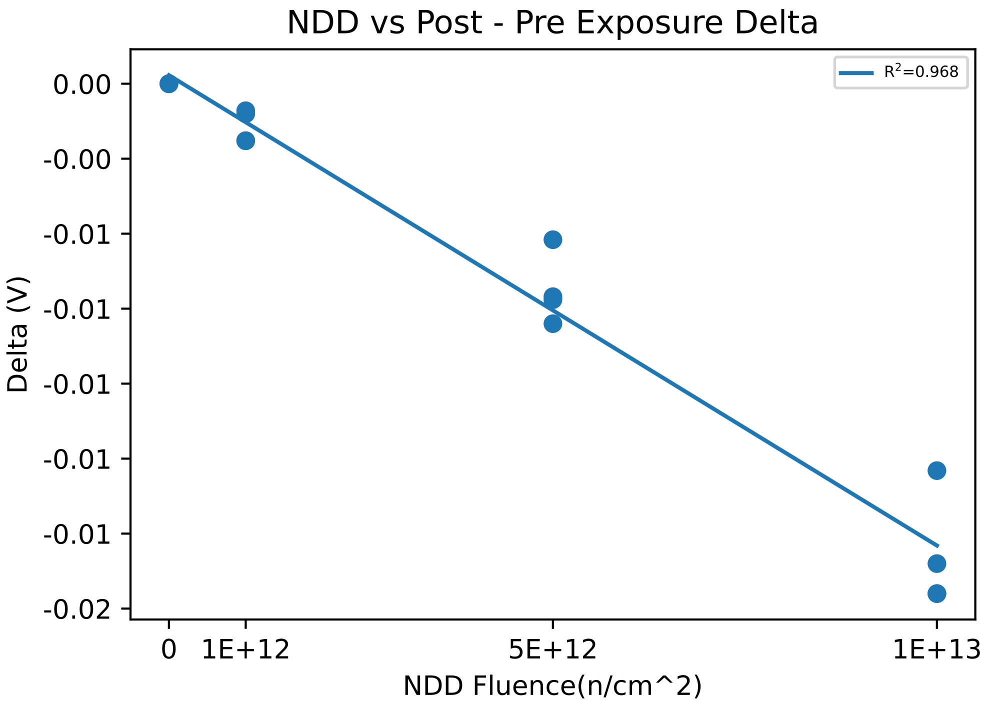
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7551	3.7551	0
2	1e+12	NDD	3.7829	3.7801	-0.0028
3	1e+12	NDD	3.7721	3.7711	-0.001
4	1e+12	NDD	3.7721	3.7699	-0.0022
5	5e+12	NDD	3.768	3.7631	-0.0049
6	5e+12	NDD	3.782	3.7748	-0.0072
7	5e+12	NDD	3.7659	3.7591	-0.0068
8	5e+12	NDD	3.7739	3.7659	-0.008
9	1e+13	NDD	3.7748	3.7591	-0.0157
10	1e+13	NDD	3.7711	3.7551	-0.016
11	1e+13	NDD	3.7541	3.7412	-0.0129
12	1e+13	NDD	3.7551	3.7381	-0.017
13	0	CORRELATION	3.7739	3.773	-0.0009
14	0	CORRELATION	3.7609	3.7609	0
15	0	CORRELATION	3.773	3.7721	-0.0009

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7609	3.7693	3.7739	0.0072597	3.7609	3.7687	3.773	0.0067412	-0.0009	-0.0006	0	0.00051962
1e+12	3.7551	3.7706	3.7829	0.01149	3.7551	3.7691	3.7801	0.010354	-0.0028	-0.0015	0	0.001249
5e+12	3.7659	3.7725	3.782	0.0072113	3.7591	3.7657	3.7748	0.0066625	-0.008	-0.006725	-0.0049	0.001315
1e+13	3.7541	3.7638	3.7748	0.010709	3.7381	3.7484	3.7591	0.010284	-0.017	-0.0154	-0.0129	0.0017569

Device Test: 17.10 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_RISE





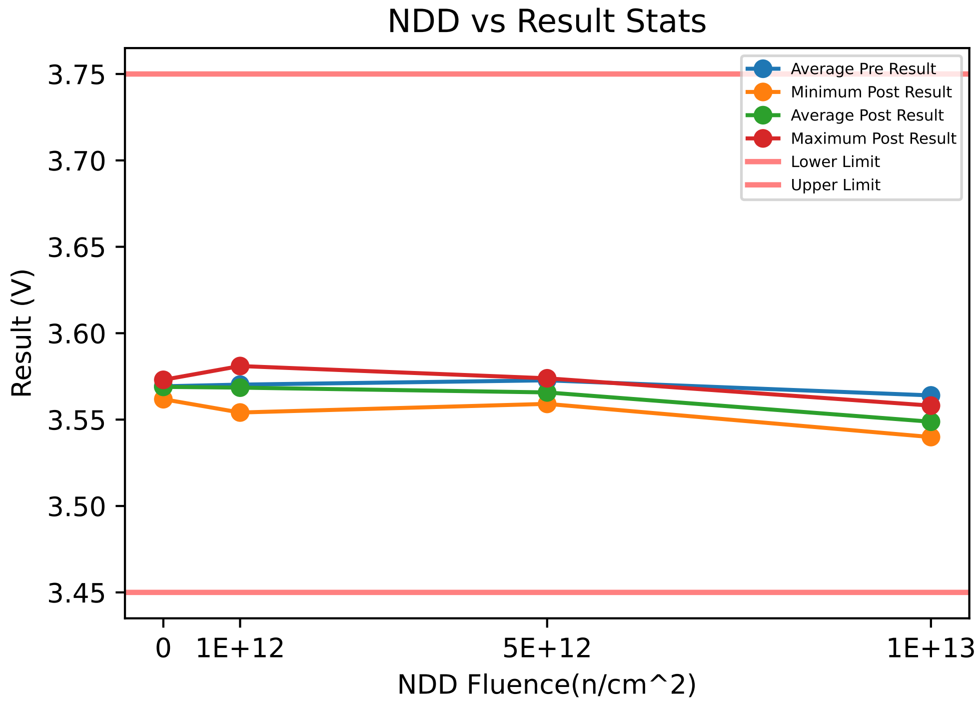
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

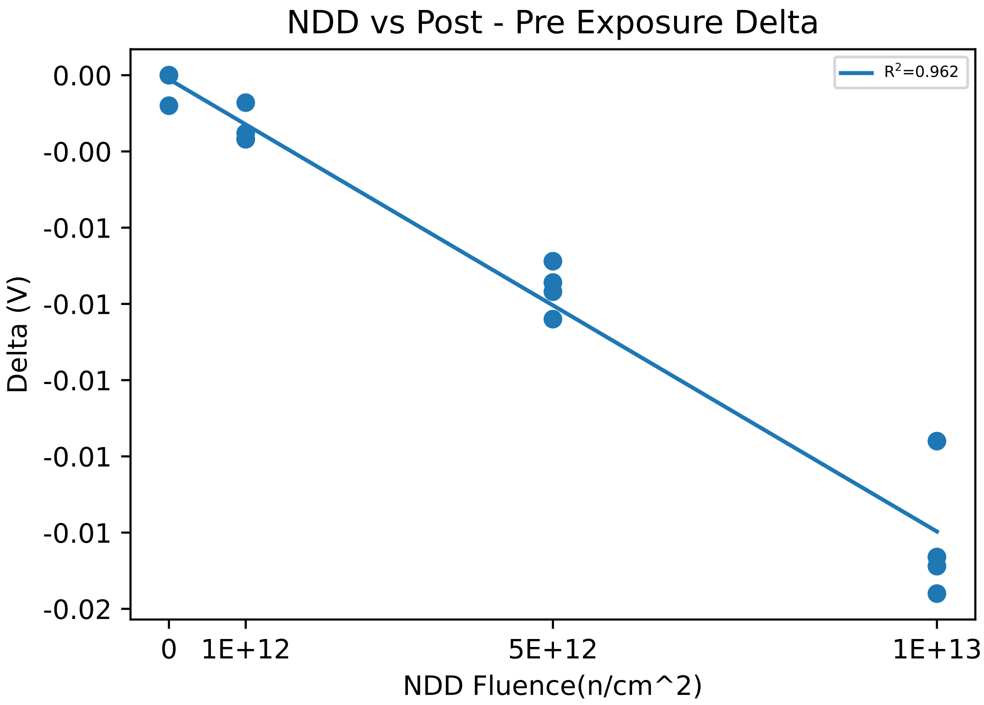
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.756	3.7551	-0.0009
2	1e+12	NDD	3.7829	3.781	-0.0019
3	1e+12	NDD	3.773	3.7711	-0.0019
4	1e+12	NDD	3.7721	3.7711	-0.001
5	5e+12	NDD	3.7711	3.7659	-0.0052
6	5e+12	NDD	3.782	3.7748	-0.0072
7	5e+12	NDD	3.7671	3.7591	-0.008
8	5e+12	NDD	3.773	3.7659	-0.0071
9	1e+13	NDD	3.7761	3.7591	-0.017
10	1e+13	NDD	3.7711	3.7551	-0.016
11	1e+13	NDD	3.7541	3.7412	-0.0129
12	1e+13	NDD	3.7551	3.7381	-0.017
13	0	CORRELATION	3.7739	3.7739	0
14	0	CORRELATION	3.7609	3.7609	0
15	0	CORRELATION	3.773	3.773	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7609	3.7693	3.7739	0.0072597	3.7609	3.7693	3.7739	0.0072597	0	0	0	0
1e+12	3.756	3.771	3.7829	0.011133	3.7551	3.7696	3.781	0.010719	-0.0019	-0.001425	-0.0009	0.00055
5e+12	3.7671	3.7733	3.782	0.0062997	3.7591	3.7664	3.7748	0.0064381	-0.008	-0.006875	-0.0052	0.0011871
1e+13	3.7541	3.7641	3.7761	0.011165	3.7381	3.7484	3.7591	0.010284	-0.017	-0.015725	-0.0129	0.0019414

Device Test: 17.11 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_FALL





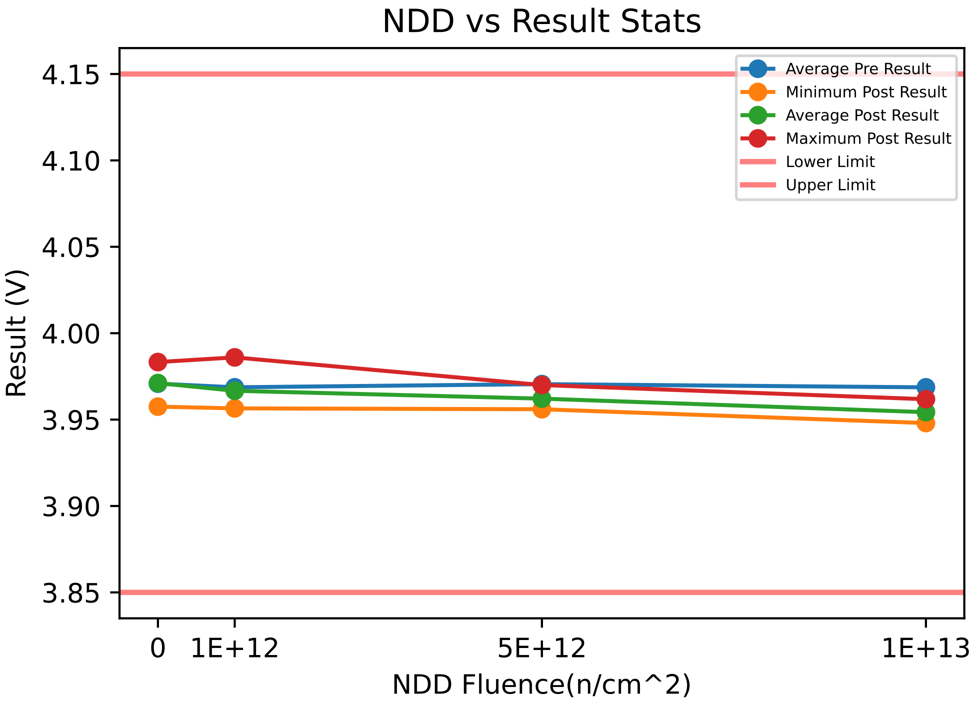
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

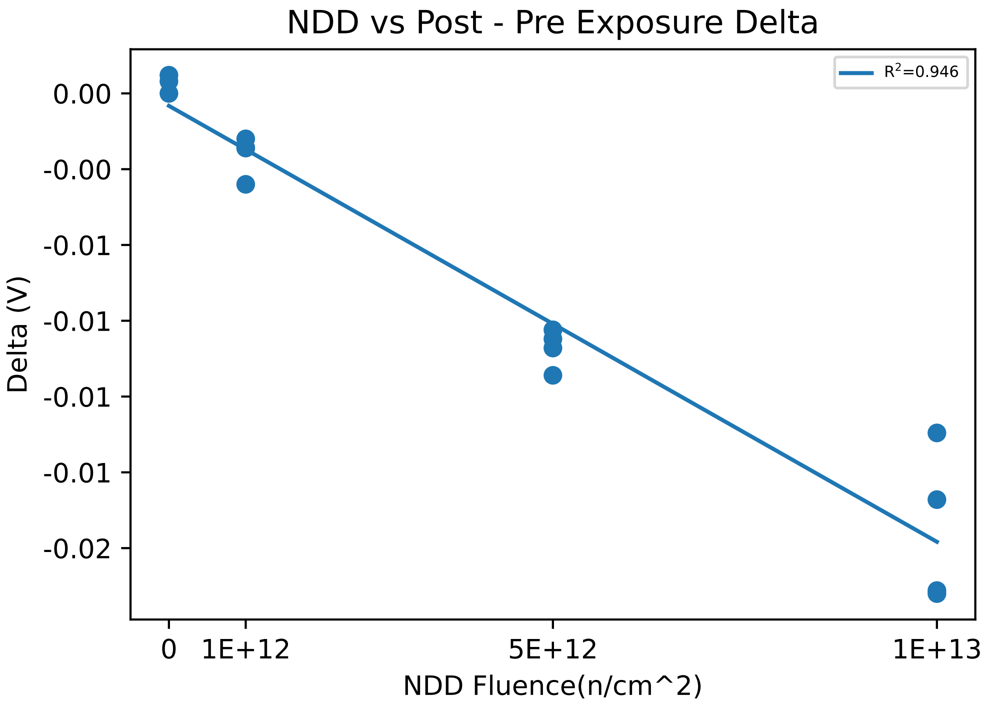
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.555	3.5541	-0.0009
2	1e+12	NDD	3.5829	3.581	-0.0019
3	1e+12	NDD	3.572	3.5699	-0.0021
4	1e+12	NDD	3.5711	3.569	-0.0021
5	5e+12	NDD	3.572	3.5659	-0.0061
6	5e+12	NDD	3.581	3.5739	-0.0071
7	5e+12	NDD	3.5659	3.5591	-0.0068
8	5e+12	NDD	3.572	3.564	-0.008
9	1e+13	NDD	3.5739	3.5581	-0.0158
10	1e+13	NDD	3.572	3.555	-0.017
11	1e+13	NDD	3.5541	3.5421	-0.012
12	1e+13	NDD	3.556	3.5399	-0.0161
13	0	CORRELATION	3.573	3.572	-0.001
14	0	CORRELATION	3.5618	3.5618	0
15	0	CORRELATION	3.573	3.573	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5618	3.5693	3.573	0.0064663	3.5618	3.5689	3.573	0.0061978	-0.001	-0.00033333	0	0.00057735
1e+12	3.555	3.5703	3.5829	0.011494	3.5541	3.5685	3.581	0.011043	-0.0021	-0.00175	-0.0009	0.00057446
5e+12	3.5659	3.5727	3.581	0.0062211	3.5591	3.5657	3.5739	0.006157	-0.008	-0.007	-0.0061	0.0007874
1e+13	3.5541	3.564	3.5739	0.010393	3.5399	3.5488	3.5581	0.0091109	-0.017	-0.015225	-0.012	0.0022096

Device Test: 17.13 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_RISE





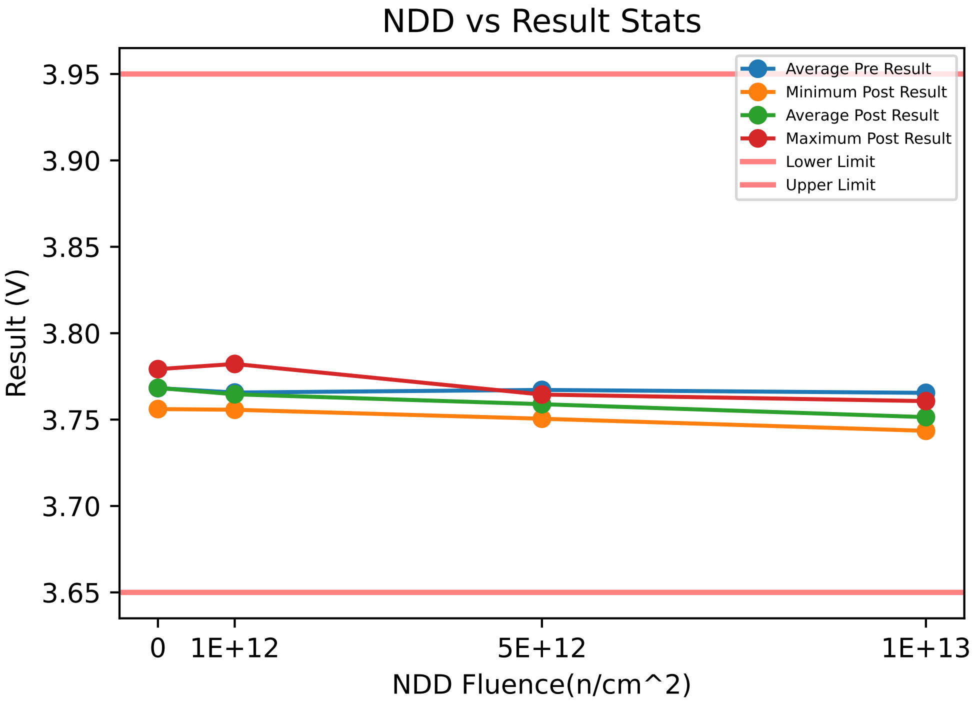
Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

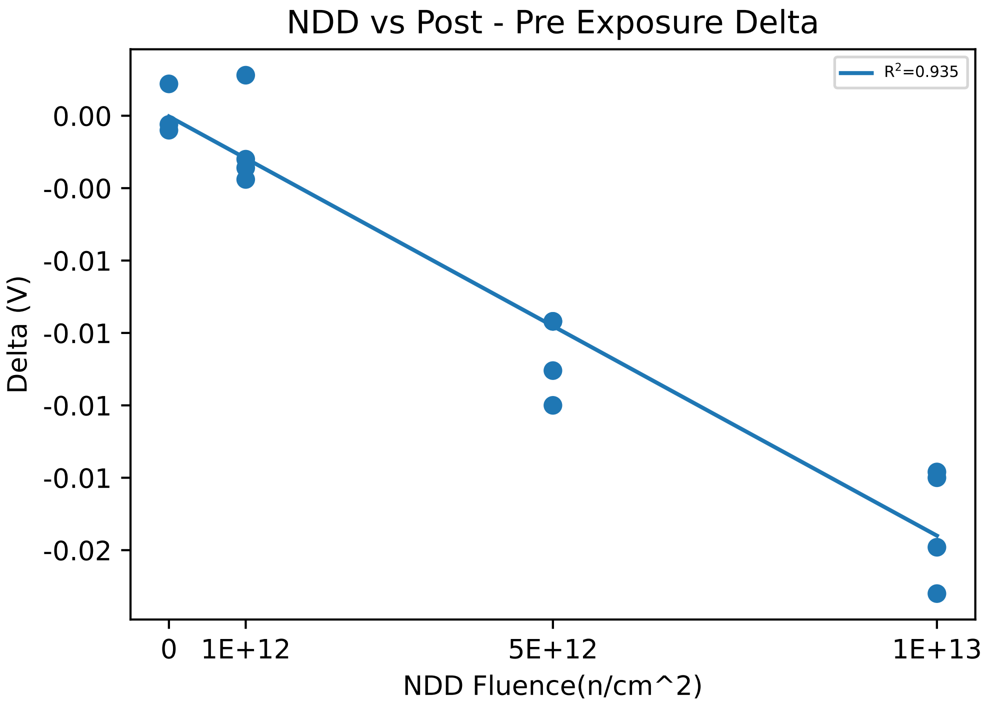
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.9597	3.9579	-0.0018
2	1e+12	NDD	3.9681	3.9663	-0.0018
3	1e+12	NDD	3.9595	3.9565	-0.003
4	1e+12	NDD	3.9875	3.986	-0.0015
5	5e+12	NDD	3.9638	3.956	-0.0078
6	5e+12	NDD	3.9705	3.9624	-0.0081
7	5e+12	NDD	3.9694	3.9601	-0.0093
8	5e+12	NDD	3.9784	3.97	-0.0084
9	1e+13	NDD	3.9614	3.948	-0.0134
10	1e+13	NDD	3.9706	3.9542	-0.0164
11	1e+13	NDD	3.9644	3.9532	-0.0112
12	1e+13	NDD	3.9783	3.9618	-0.0165
13	0	CORRELATION	3.9722	3.9726	0.0004
14	0	CORRELATION	3.9575	3.9575	0
15	0	CORRELATION	3.9827	3.9833	0.0006

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9575	3.9708	3.9827	0.012658	3.9575	3.9711	3.9833	0.012962	0	0.00033333	0.0006	0.00030551
1e+12	3.9595	3.9687	3.9875	0.013159	3.9565	3.9667	3.986	0.013591	-0.003	-0.002025	-0.0015	0.00066521
5e+12	3.9638	3.9705	3.9784	0.0060141	3.956	3.9621	3.97	0.0058796	-0.0093	-0.0084	-0.0078	0.00064807
1e+13	3.9614	3.9687	3.9783	0.0074732	3.948	3.9543	3.9618	0.0056909	-0.0165	-0.014375	-0.0112	0.0025591

Device Test: 17.14 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_FALL





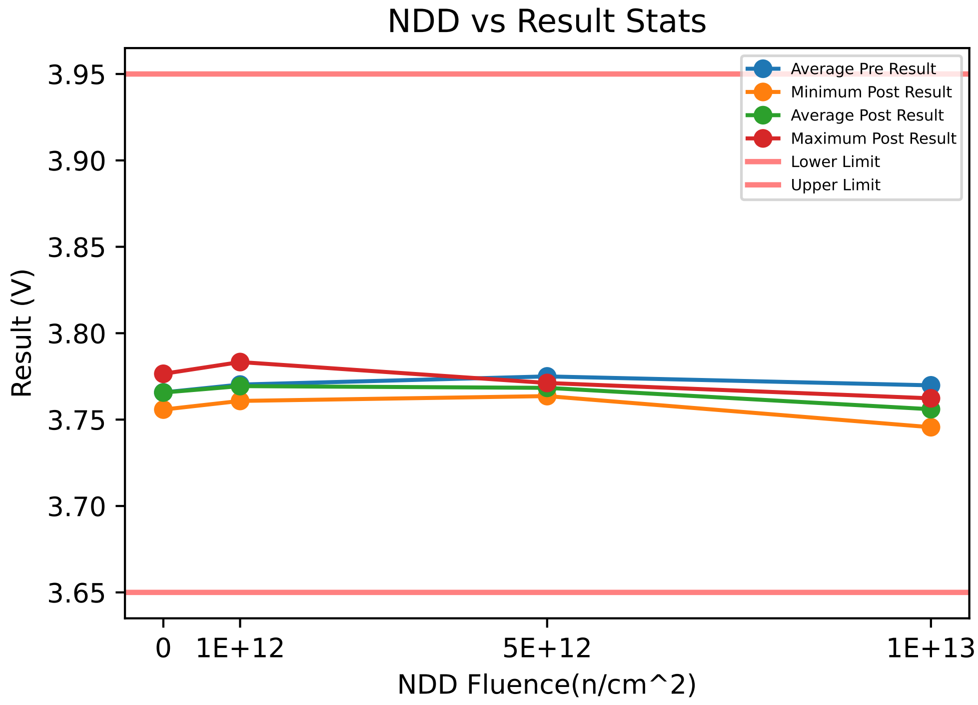
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

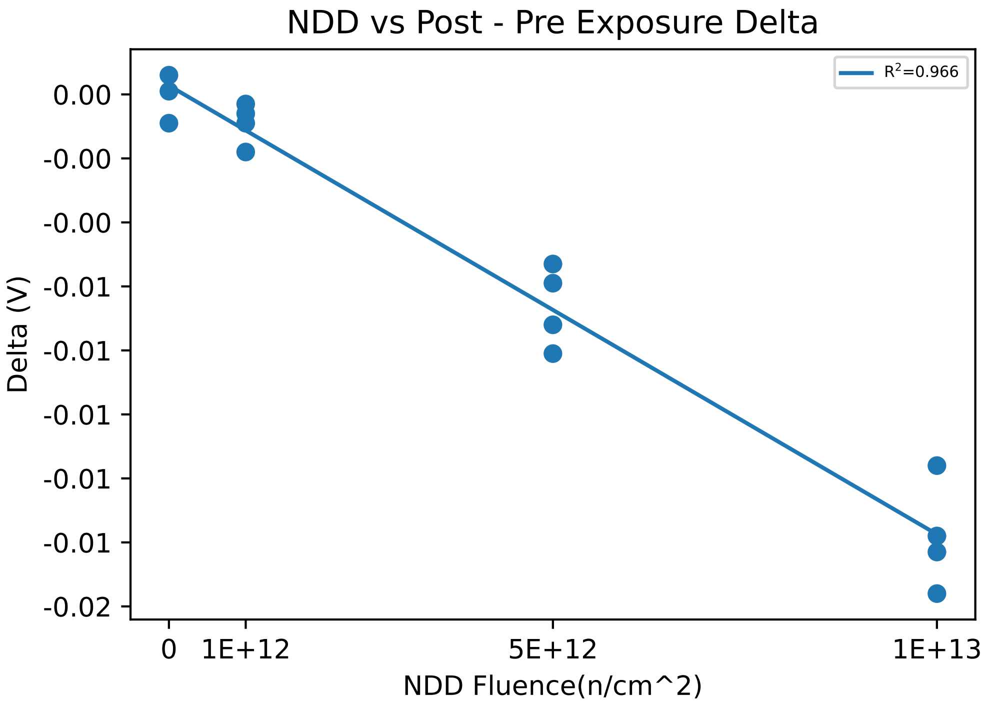
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7577	3.7559	-0.0018
2	1e+12	NDD	3.767	3.7648	-0.0022
3	1e+12	NDD	3.7572	3.7557	-0.0015
4	1e+12	NDD	3.7808	3.7822	0.0014
5	5e+12	NDD	3.7605	3.7505	-0.01
6	5e+12	NDD	3.7669	3.7598	-0.0071
7	5e+12	NDD	3.768	3.7609	-0.0071
8	5e+12	NDD	3.7733	3.7645	-0.0088
9	1e+13	NDD	3.76	3.7435	-0.0165
10	1e+13	NDD	3.7633	3.751	-0.0123
11	1e+13	NDD	3.763	3.7505	-0.0125
12	1e+13	NDD	3.7756	3.7607	-0.0149
13	0	CORRELATION	3.7702	3.7697	-0.0005
14	0	CORRELATION	3.7564	3.7561	-0.0003
15	0	CORRELATION	3.7781	3.7792	0.0011

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7564	3.7682	3.7781	0.010983	3.7561	3.7683	3.7792	0.01161	-0.0005	0.0001	0.0011	0.00087178
1e+12	3.7572	3.7657	3.7808	0.011045	3.7557	3.7647	3.7822	0.012446	-0.0022	-0.001025	0.0014	0.0016419
5e+12	3.7605	3.7672	3.7733	0.0052544	3.7505	3.7589	3.7645	0.0059645	-0.01	-0.00825	-0.0071	0.0014154
1e+13	3.76	3.7655	3.7756	0.0069125	3.7435	3.7514	3.7607	0.0070679	-0.0165	-0.01405	-0.0123	0.0020158

Device Test: 17.16 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_RISE





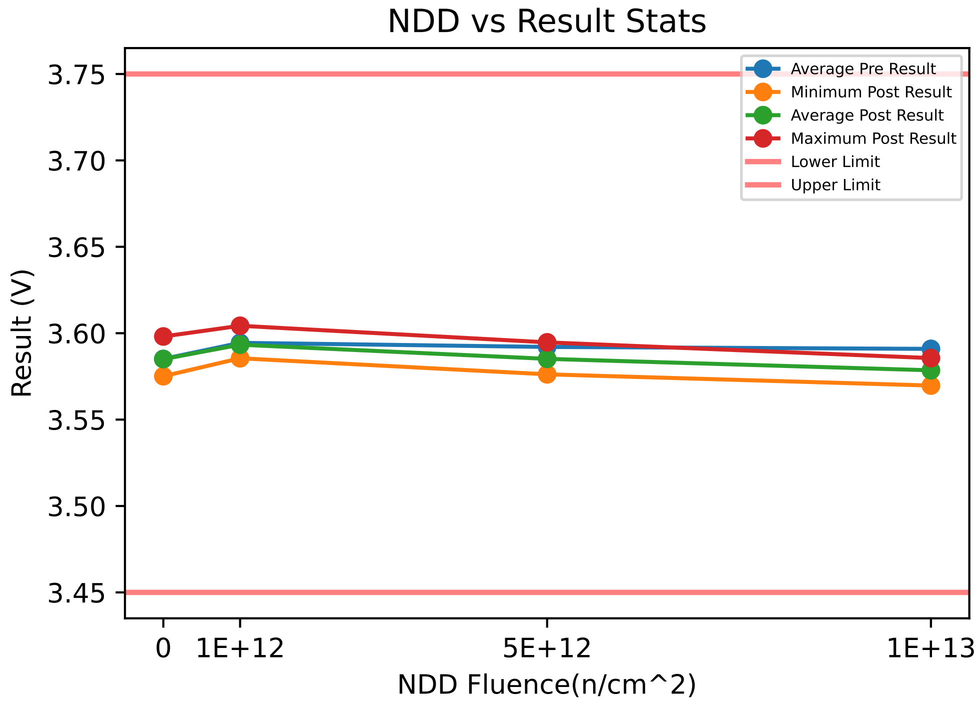
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

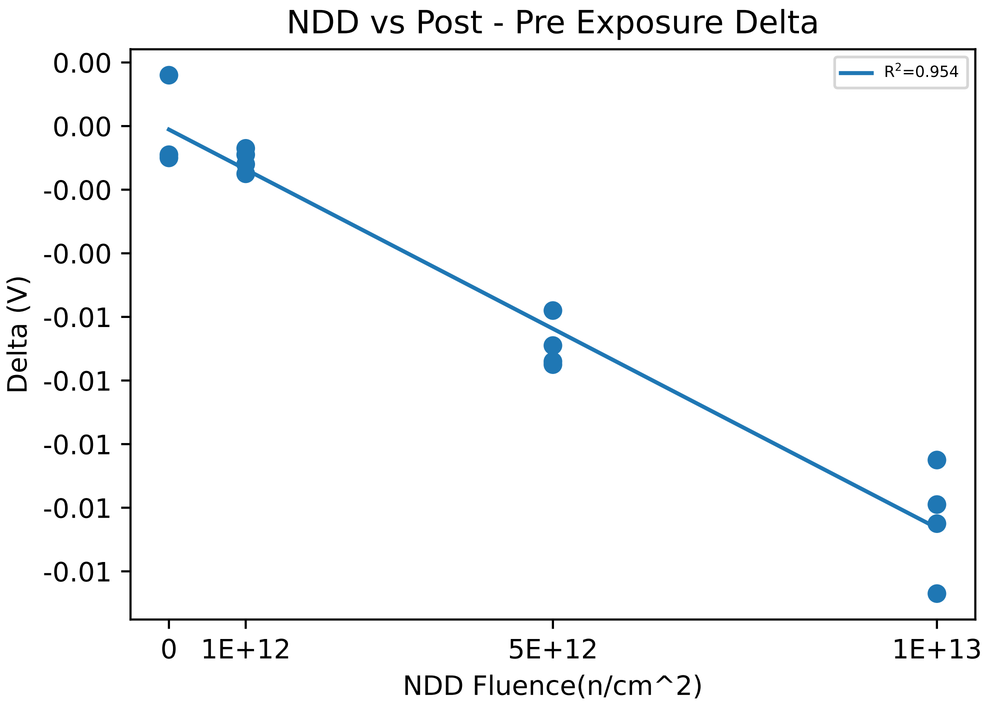
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7614	3.7608	-0.0006
2	1e+12	NDD	3.7634	3.7625	-0.0009
3	1e+12	NDD	3.7727	3.7709	-0.0018
4	1e+12	NDD	3.7836	3.7833	-0.0003
5	5e+12	NDD	3.7781	3.7709	-0.0072
6	5e+12	NDD	3.7765	3.7712	-0.0053
7	5e+12	NDD	3.7695	3.7636	-0.0059
8	5e+12	NDD	3.7759	3.7678	-0.0081
9	1e+13	NDD	3.7599	3.7456	-0.0143
10	1e+13	NDD	3.7761	3.7623	-0.0138
11	1e+13	NDD	3.7656	3.754	-0.0116
12	1e+13	NDD	3.7777	3.7621	-0.0156
13	0	CORRELATION	3.7552	3.7558	0.0006
14	0	CORRELATION	3.7646	3.7647	0.0001
15	0	CORRELATION	3.7774	3.7765	-0.0009

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7552	3.7657	3.7774	0.011143	3.7558	3.7657	3.7765	0.010384	-0.0009	-6.6667e-05	0.0006	0.00076376
1e+12	3.7614	3.7703	3.7836	0.010157	3.7608	3.7694	3.7833	0.01028	-0.0018	-0.0009	-0.0003	0.00064807
5e+12	3.7695	3.775	3.7781	0.0037824	3.7636	3.7684	3.7712	0.0035349	-0.0081	-0.006625	-0.0053	0.0012633
1e+13	3.7599	3.7698	3.7777	0.0085195	3.7456	3.756	3.7623	0.0079385	-0.0156	-0.013825	-0.0116	0.0016661

Device Test: 17.17 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_FALL





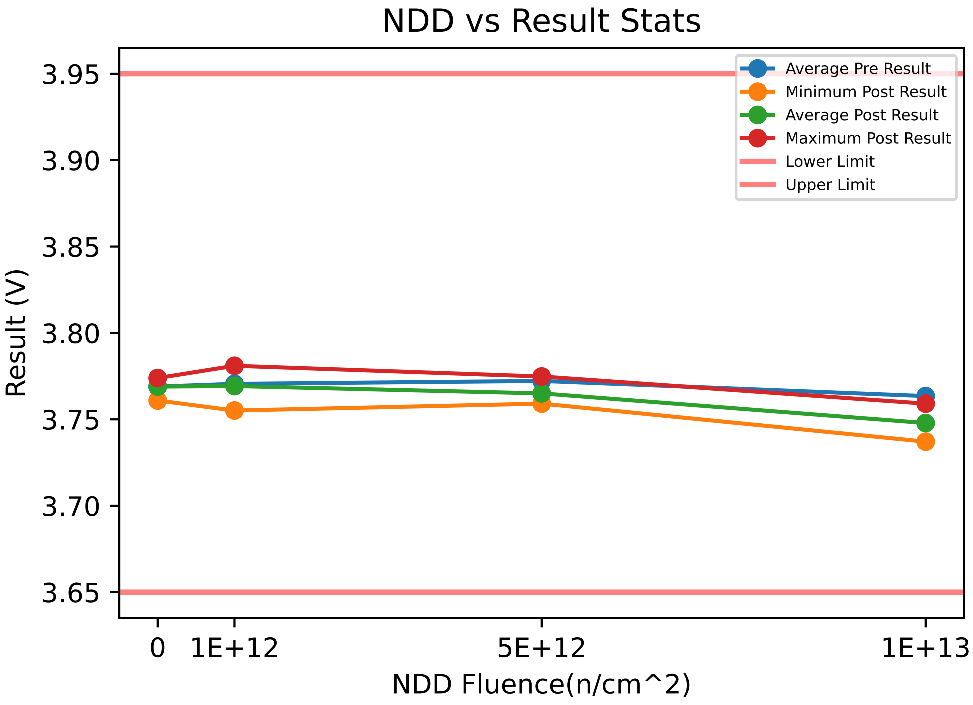
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

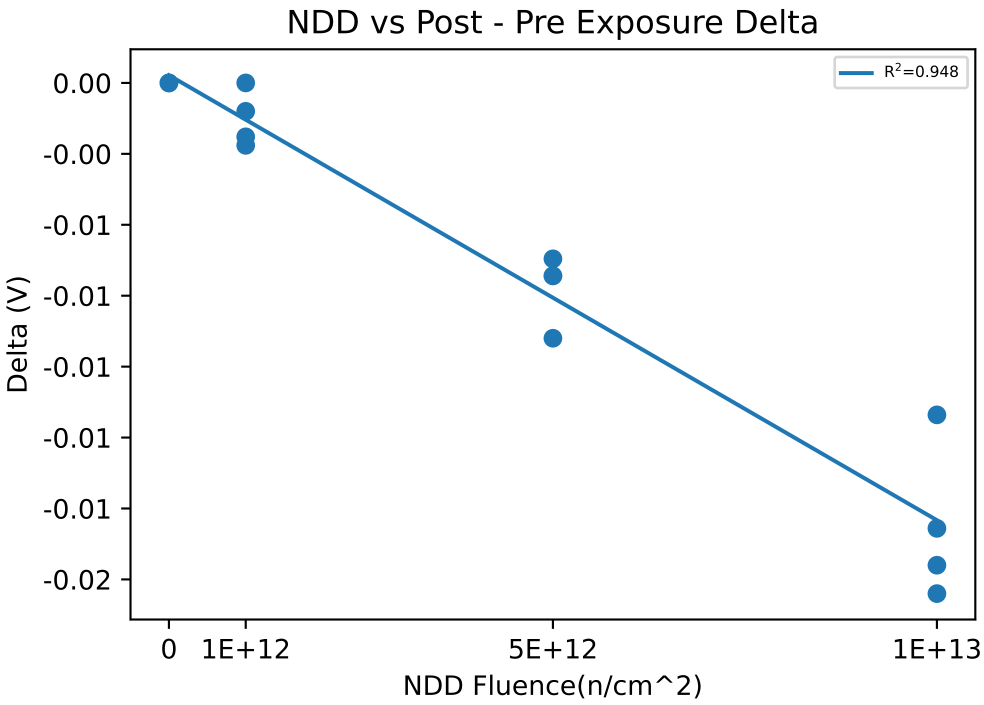
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.5862	3.5855	-0.0007
2	1e+12	NDD	3.5954	3.5939	-0.0015
3	1e+12	NDD	3.5906	3.5897	-0.0009
4	1e+12	NDD	3.6055	3.6043	-0.0012
5	5e+12	NDD	3.5888	3.5814	-0.0074
6	5e+12	NDD	3.6016	3.5947	-0.0069
7	5e+12	NDD	3.5837	3.5762	-0.0075
8	5e+12	NDD	3.5941	3.5883	-0.0058
9	1e+13	NDD	3.5822	3.5697	-0.0125
10	1e+13	NDD	3.5924	3.5805	-0.0119
11	1e+13	NDD	3.5888	3.5783	-0.0105
12	1e+13	NDD	3.6003	3.5856	-0.0147
13	0	CORRELATION	3.5827	3.5818	-0.0009
14	0	CORRELATION	3.5735	3.5751	0.0016
15	0	CORRELATION	3.5991	3.5981	-0.001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5735	3.5851	3.5991	0.012968	3.5751	3.585	3.5981	0.011829	-0.001	-0.0001	0.0016	0.0014731
1e+12	3.5862	3.5944	3.6055	0.0082843	3.5855	3.5934	3.6043	0.0080654	-0.0015	-0.001075	-0.0007	0.00035
5e+12	3.5837	3.592	3.6016	0.0076527	3.5762	3.5852	3.5947	0.0080683	-0.0075	-0.0069	-0.0058	0.00077889
1e+13	3.5822	3.5909	3.6003	0.0075434	3.5697	3.5785	3.5856	0.0066304	-0.0147	-0.0124	-0.0105	0.0017474

Device Test: 17.19 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_RISE





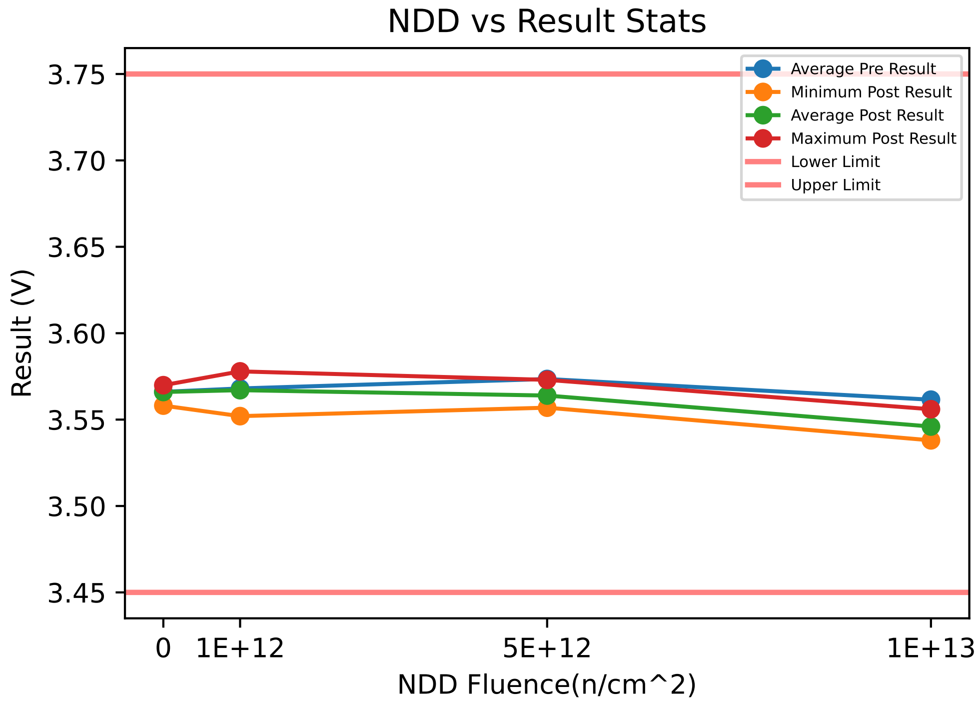
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

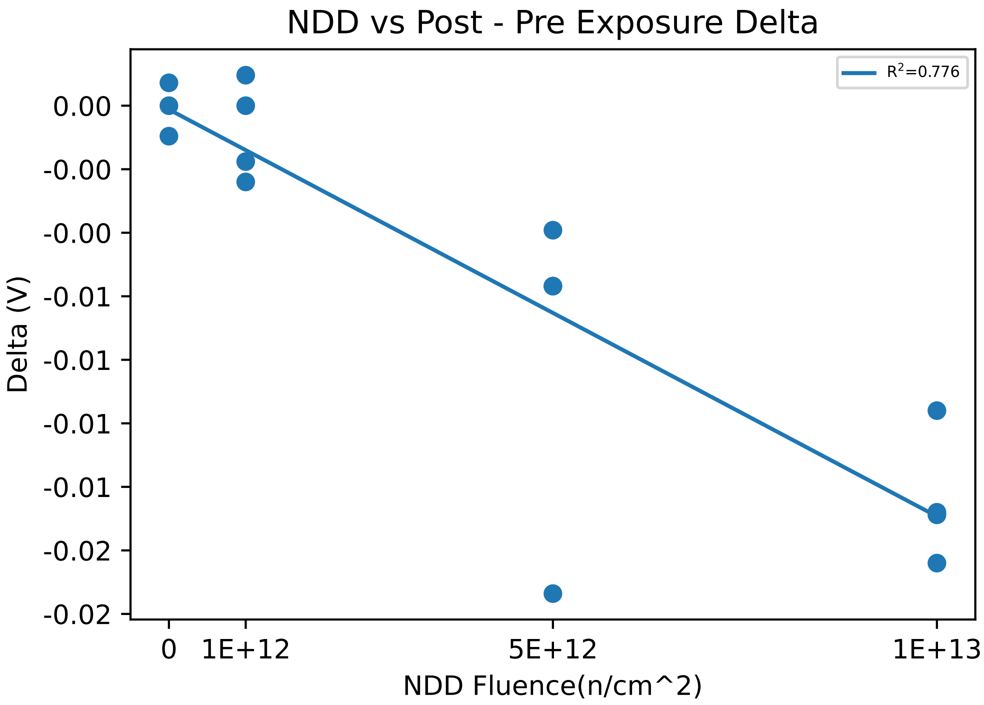
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7551	3.7551	0
2	1e+12	NDD	3.7829	3.781	-0.0019
3	1e+12	NDD	3.7721	3.7711	-0.001
4	1e+12	NDD	3.7721	3.7699	-0.0022
5	5e+12	NDD	3.7699	3.7631	-0.0068
6	5e+12	NDD	3.781	3.7748	-0.0062
7	5e+12	NDD	3.7659	3.7591	-0.0068
8	5e+12	NDD	3.7721	3.7631	-0.009
9	1e+13	NDD	3.7748	3.7591	-0.0157
10	1e+13	NDD	3.7711	3.7541	-0.017
11	1e+13	NDD	3.7529	3.7412	-0.0117
12	1e+13	NDD	3.7551	3.7371	-0.018
13	0	CORRELATION	3.7739	3.7739	0
14	0	CORRELATION	3.7609	3.7609	0
15	0	CORRELATION	3.7721	3.7721	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7609	3.769	3.7739	0.0070437	3.7609	3.769	3.7739	0.0070437	0	0	0	0
1e+12	3.7551	3.7706	3.7829	0.01149	3.7551	3.7693	3.781	0.010679	-0.0022	-0.001275	0	0.00099121
5e+12	3.7659	3.7722	3.781	0.0063882	3.7591	3.765	3.7748	0.006784	-0.009	-0.0072	-0.0062	0.0012329
1e+13	3.7529	3.7635	3.7748	0.011081	3.7371	3.7479	3.7591	0.010415	-0.018	-0.0156	-0.0117	0.0027653

Device Test: 17.2 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_FALL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

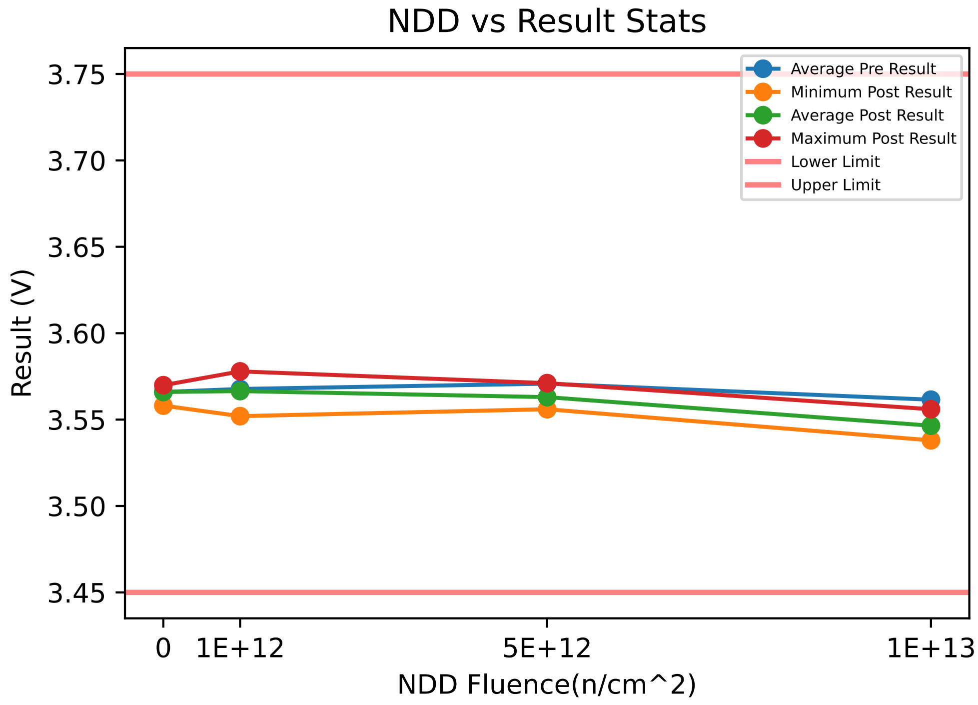
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

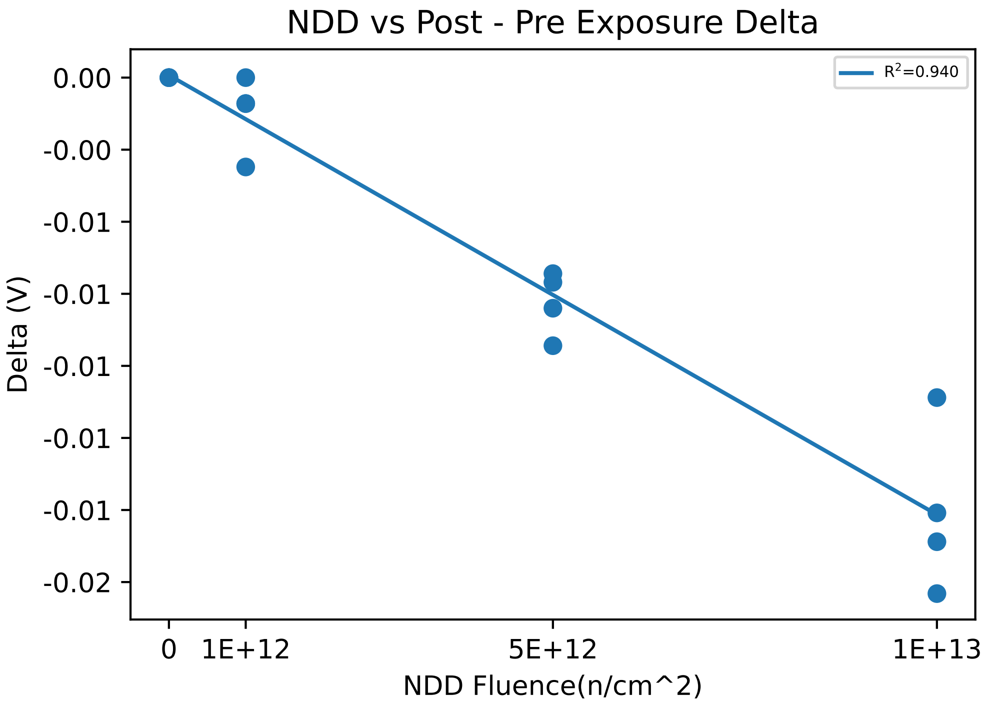
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.555	3.552	-0.003
2	1e+12	NDD	3.5801	3.5779	-0.0022
3	1e+12	NDD	3.5699	3.5711	0.0012
4	1e+12	NDD	3.5671	3.5671	0
5	5e+12	NDD	3.581	3.5618	-0.0192
6	5e+12	NDD	3.5779	3.573	-0.0049
7	5e+12	NDD	3.564	3.5569	-0.0071
8	5e+12	NDD	3.5711	3.564	-0.0071
9	1e+13	NDD	3.572	3.556	-0.016
10	1e+13	NDD	3.569	3.551	-0.018
11	1e+13	NDD	3.551	3.539	-0.012
12	1e+13	NDD	3.5541	3.538	-0.0161
13	0	CORRELATION	3.5711	3.5699	-0.0012
14	0	CORRELATION	3.5581	3.5581	0
15	0	CORRELATION	3.569	3.5699	0.0009

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5581	3.5661	3.5711	0.0069788	3.5581	3.566	3.5699	0.0068127	-0.0012	-0.0001	0.0009	0.0010536
1e+12	3.555	3.568	3.5801	0.010325	3.552	3.567	3.5779	0.010964	-0.003	-0.001	0.0012	0.0019391
5e+12	3.564	3.5735	3.581	0.0075635	3.5569	3.5639	3.573	0.0067386	-0.0192	-0.009575	-0.0049	0.0064999
1e+13	3.551	3.5615	3.572	0.010512	3.538	3.546	3.556	0.0089069	-0.018	-0.015525	-0.012	0.0025237

Device Test: 17.20 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_FALL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

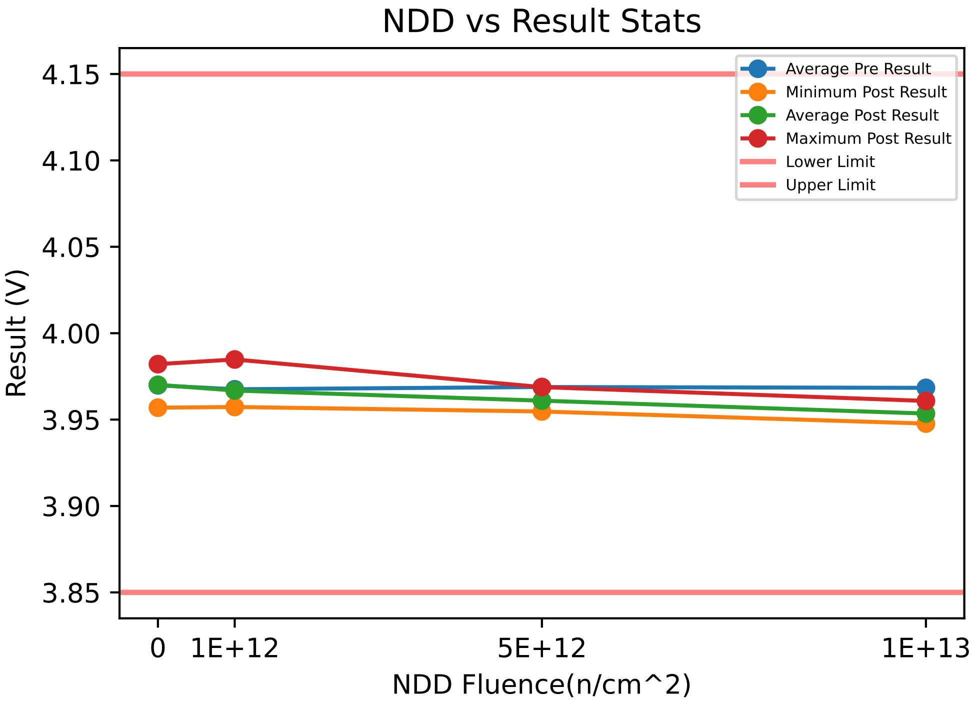
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

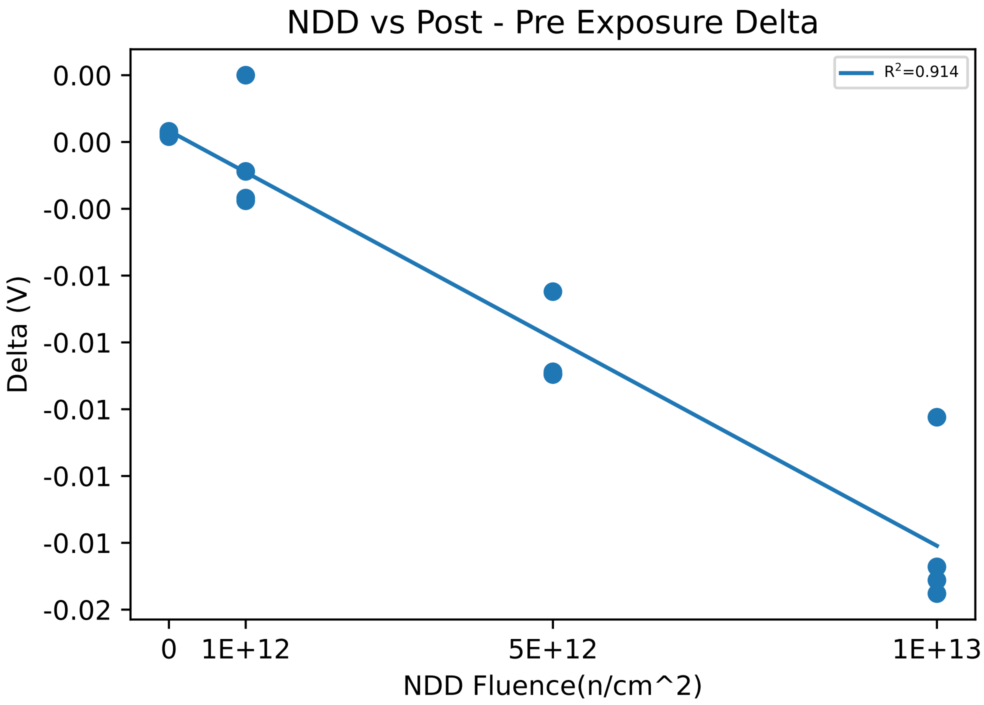
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.5529	3.552	-0.0009
2	1e+12	NDD	3.581	3.5779	-0.0031
3	1e+12	NDD	3.569	3.569	0
4	1e+12	NDD	3.568	3.5671	-0.0009
5	5e+12	NDD	3.5711	3.5631	-0.008
6	5e+12	NDD	3.5779	3.5711	-0.0068
7	5e+12	NDD	3.5631	3.556	-0.0071
8	5e+12	NDD	3.5711	3.5618	-0.0093
9	1e+13	NDD	3.5711	3.556	-0.0151
10	1e+13	NDD	3.5699	3.552	-0.0179
11	1e+13	NDD	3.551	3.5399	-0.0111
12	1e+13	NDD	3.5541	3.538	-0.0161
13	0	CORRELATION	3.5699	3.5699	0
14	0	CORRELATION	3.5581	3.5581	0
15	0	CORRELATION	3.5699	3.5699	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5581	3.566	3.5699	0.0068127	3.5581	3.566	3.5699	0.0068127	0	0	0	0
1e+12	3.5529	3.5677	3.581	0.011514	3.552	3.5665	3.5779	0.010752	-0.0031	-0.001225	0	0.00132
5e+12	3.5631	3.5708	3.5779	0.006052	3.556	3.563	3.5711	0.0062199	-0.0093	-0.0078	-0.0068	0.0011225
1e+13	3.551	3.5615	3.5711	0.010452	3.538	3.5465	3.556	0.0088752	-0.0179	-0.01505	-0.0111	0.0028769

Device Test: 17.22 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_RISE





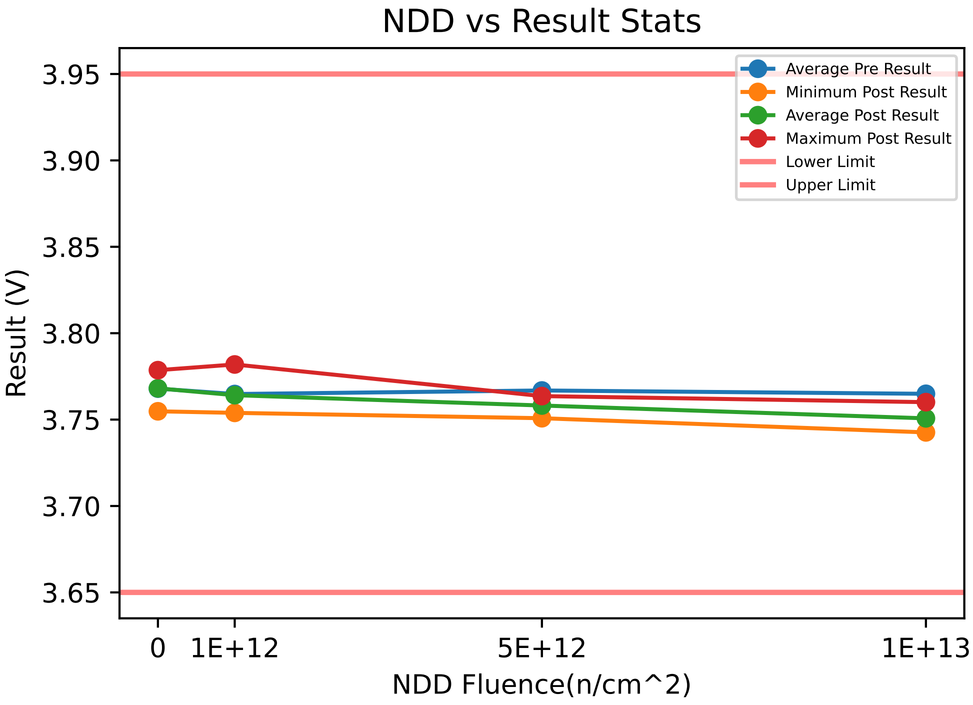
Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

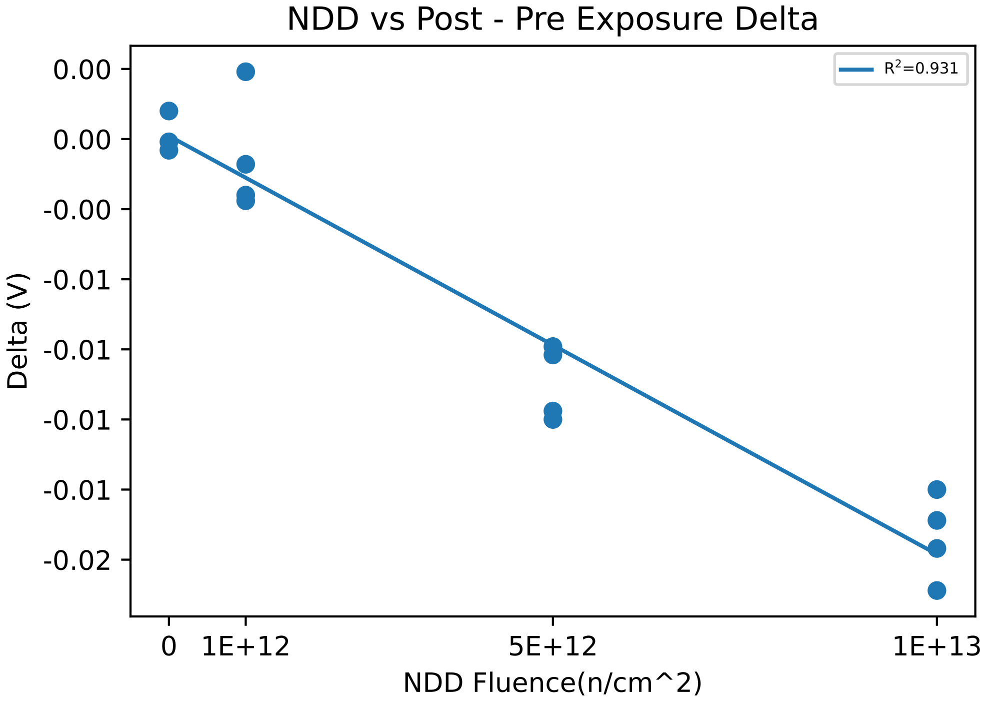
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.9584	3.9573	-0.0011
2	1e+12	NDD	3.9675	3.9653	-0.0022
3	1e+12	NDD	3.9574	3.9599	0.0025
4	1e+12	NDD	3.9869	3.9848	-0.0021
5	5e+12	NDD	3.9603	3.9547	-0.0056
6	5e+12	NDD	3.9695	3.9608	-0.0087
7	5e+12	NDD	3.9681	3.9595	-0.0086
8	5e+12	NDD	3.9775	3.9688	-0.0087
9	1e+13	NDD	3.9636	3.9477	-0.0159
10	1e+13	NDD	3.9694	3.953	-0.0164
11	1e+13	NDD	3.9628	3.9525	-0.0103
12	1e+13	NDD	3.9777	3.9608	-0.0169
13	0	CORRELATION	3.9712	3.9714	0.0002
14	0	CORRELATION	3.9566	3.9569	0.0003
15	0	CORRELATION	3.9817	3.9821	0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9566	3.9698	3.9817	0.012606	3.9569	3.9701	3.9821	0.012648	0.0002	0.0003	0.0004	0.0001
1e+12	3.9574	3.9676	3.9869	0.013677	3.9573	3.9668	3.9848	0.012438	-0.0022	-0.000725	0.0025	0.0022066
5e+12	3.9603	3.9689	3.9775	0.0070453	3.9547	3.9609	3.9688	0.0058541	-0.0087	-0.0079	-0.0056	0.0015341
1e+13	3.9628	3.9684	3.9777	0.0068772	3.9477	3.9535	3.9608	0.0054216	-0.0169	-0.014875	-0.0103	0.0030772

Device Test: 17.23 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_FALL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

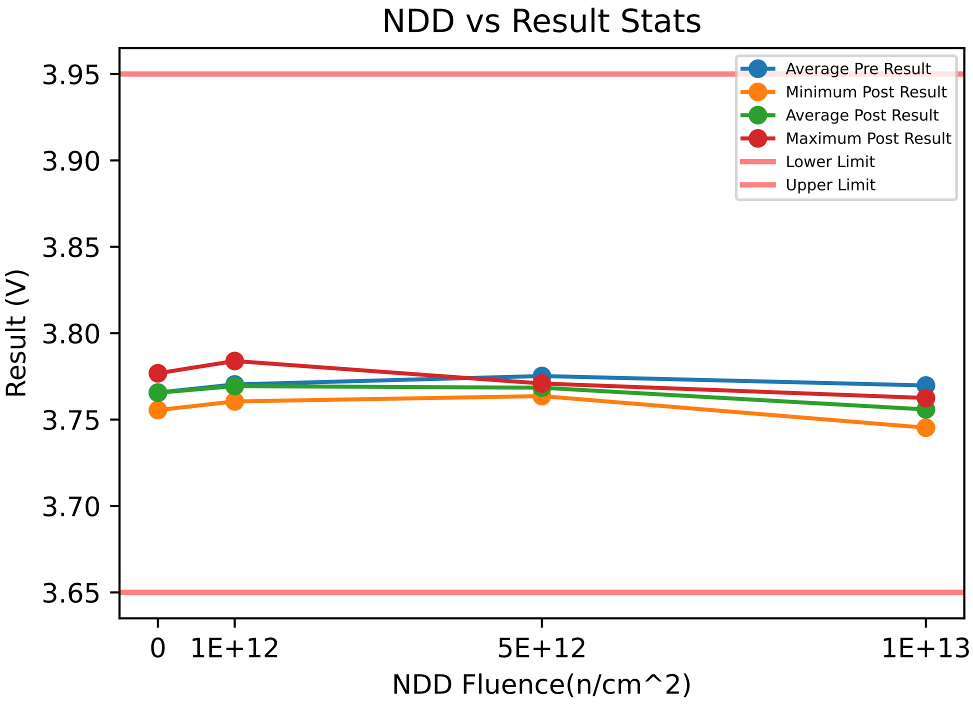
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

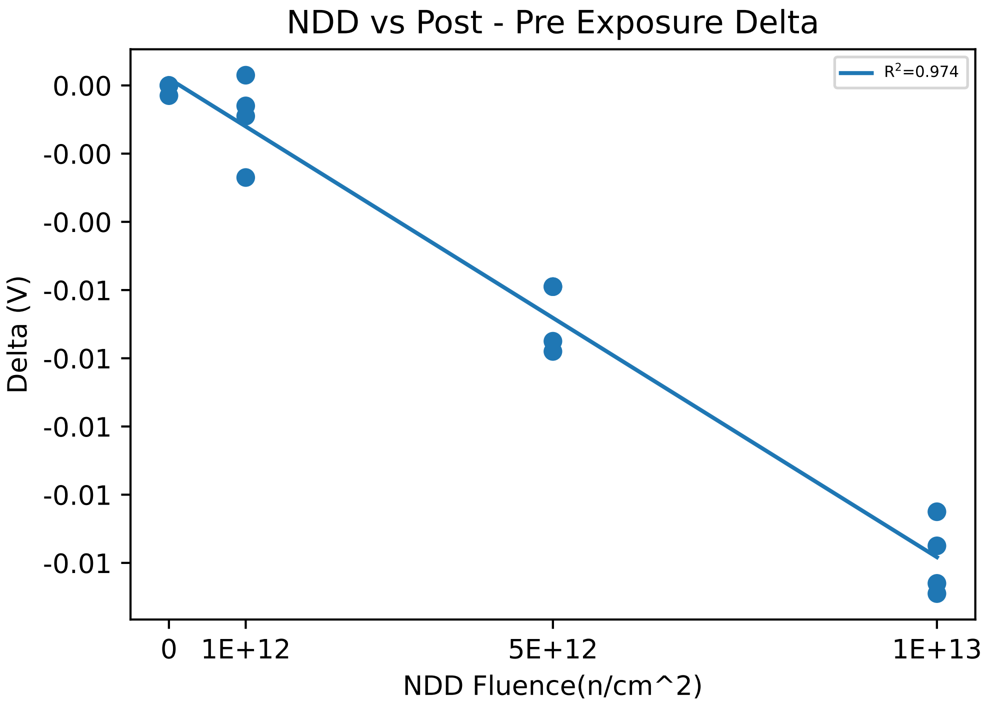
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7568	3.7559	-0.0009
2	1e+12	NDD	3.767	3.7648	-0.0022
3	1e+12	NDD	3.7559	3.7539	-0.002
4	1e+12	NDD	3.7795	3.7819	0.0024
5	5e+12	NDD	3.7608	3.7508	-0.01
6	5e+12	NDD	3.7656	3.7582	-0.0074
7	5e+12	NDD	3.7677	3.76	-0.0077
8	5e+12	NDD	3.7733	3.7636	-0.0097
9	1e+13	NDD	3.7587	3.7426	-0.0161
10	1e+13	NDD	3.7633	3.7497	-0.0136
11	1e+13	NDD	3.763	3.7505	-0.0125
12	1e+13	NDD	3.7747	3.7601	-0.0146
13	0	CORRELATION	3.7699	3.7709	0.001
14	0	CORRELATION	3.7549	3.7548	-0.0001
15	0	CORRELATION	3.779	3.7786	-0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7549	3.7679	3.779	0.01217	3.7548	3.7681	3.7786	0.012145	-0.0004	0.00016667	0.001	0.00073711
1e+12	3.7559	3.7648	3.7795	0.011017	3.7539	3.7641	3.7819	0.012762	-0.0022	-0.000675	0.0024	0.0021282
5e+12	3.7608	3.7668	3.7733	0.0051798	3.7508	3.7581	3.7636	0.0053898	-0.01	-0.0087	-0.0074	0.0013392
1e+13	3.7587	3.7649	3.7747	0.0068471	3.7426	3.7507	3.7601	0.0071881	-0.0161	-0.0142	-0.0125	0.0015297

Device Test: 17.25 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_RISE





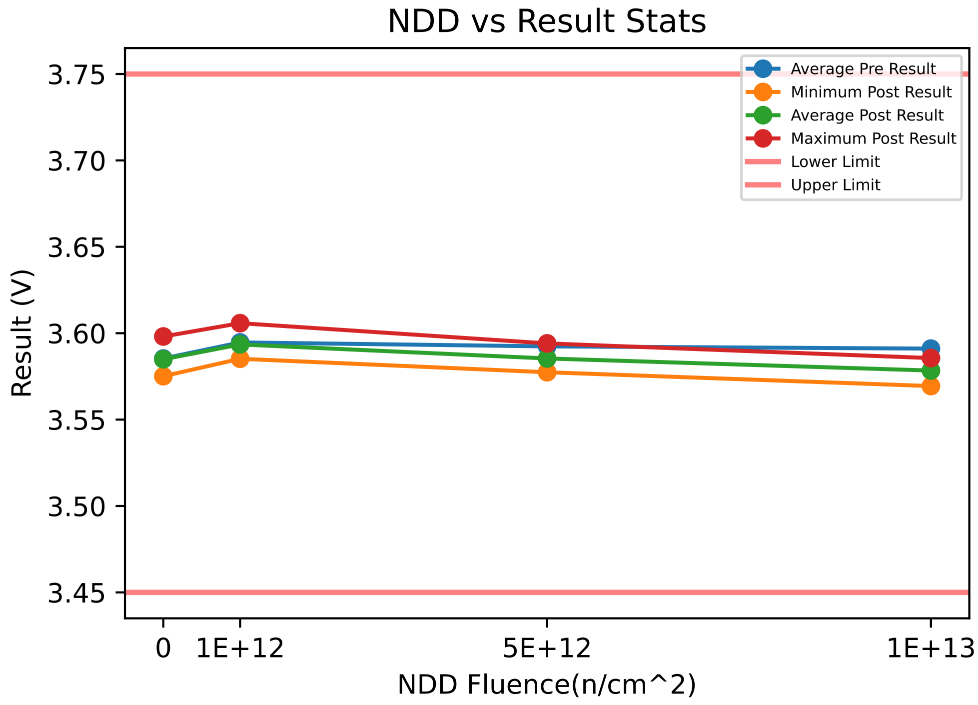
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

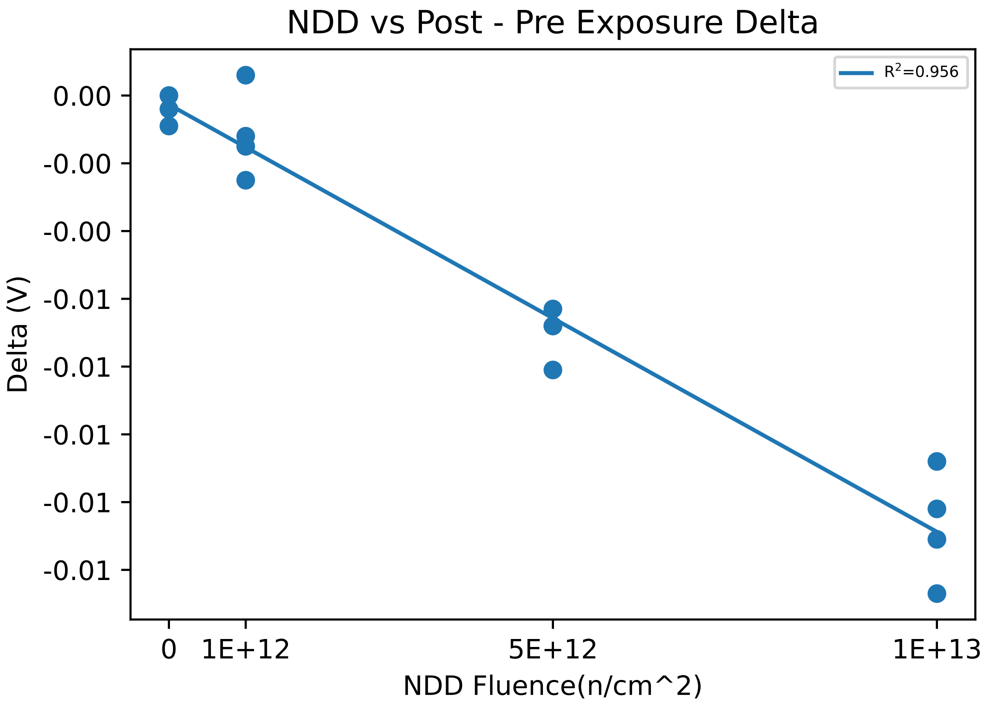
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7614	3.7605	-0.0009
2	1e+12	NDD	3.7631	3.7625	-0.0006
3	1e+12	NDD	3.7733	3.7706	-0.0027
4	1e+12	NDD	3.7836	3.7839	0.0003
5	5e+12	NDD	3.7787	3.7709	-0.0078
6	5e+12	NDD	3.7768	3.7709	-0.0059
7	5e+12	NDD	3.7695	3.7636	-0.0059
8	5e+12	NDD	3.7759	3.7684	-0.0075
9	1e+13	NDD	3.7599	3.7453	-0.0146
10	1e+13	NDD	3.7758	3.7623	-0.0135
11	1e+13	NDD	3.7659	3.7534	-0.0125
12	1e+13	NDD	3.7774	3.7625	-0.0149
13	0	CORRELATION	3.7555	3.7555	0
14	0	CORRELATION	3.7646	3.7643	-0.0003
15	0	CORRELATION	3.7768	3.7768	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7555	3.7656	3.7768	0.010688	3.7555	3.7655	3.7768	0.010703	-0.0003	-0.0001	0	0.00017321
1e+12	3.7614	3.7704	3.7836	0.010278	3.7605	3.7694	3.7839	0.010622	-0.0027	-0.000975	0.0003	0.001258
5e+12	3.7695	3.7752	3.7787	0.0039911	3.7636	3.7685	3.7709	0.0034414	-0.0078	-0.006775	-0.0059	0.0010178
1e+13	3.7599	3.7698	3.7774	0.008306	3.7453	3.7559	3.7625	0.0082286	-0.0149	-0.013875	-0.0125	0.0010966

Device Test: 17.26 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_FALL





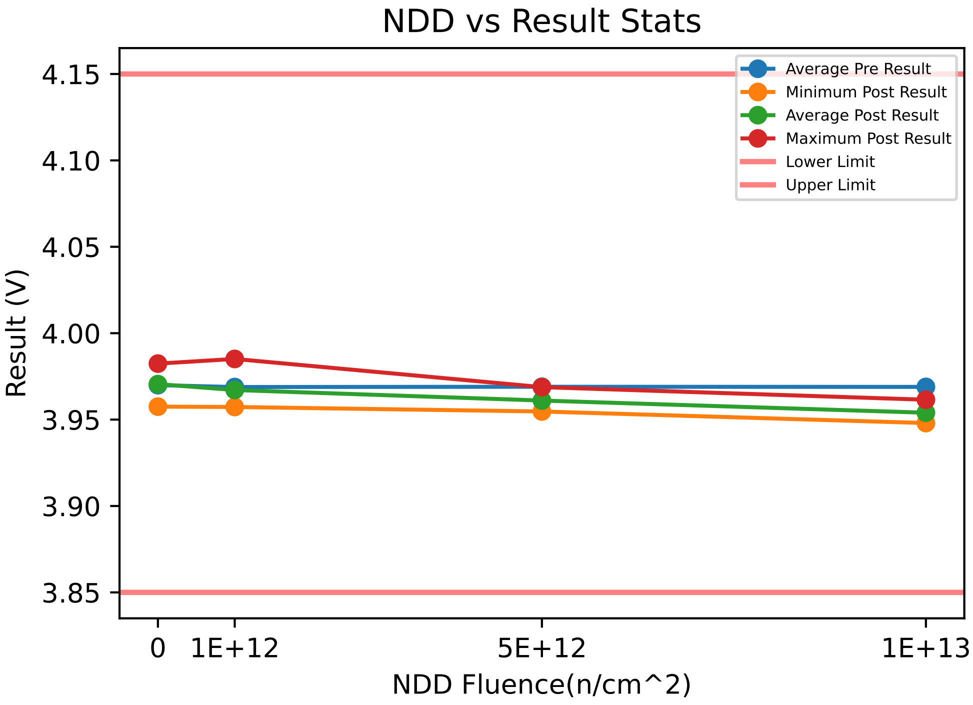
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

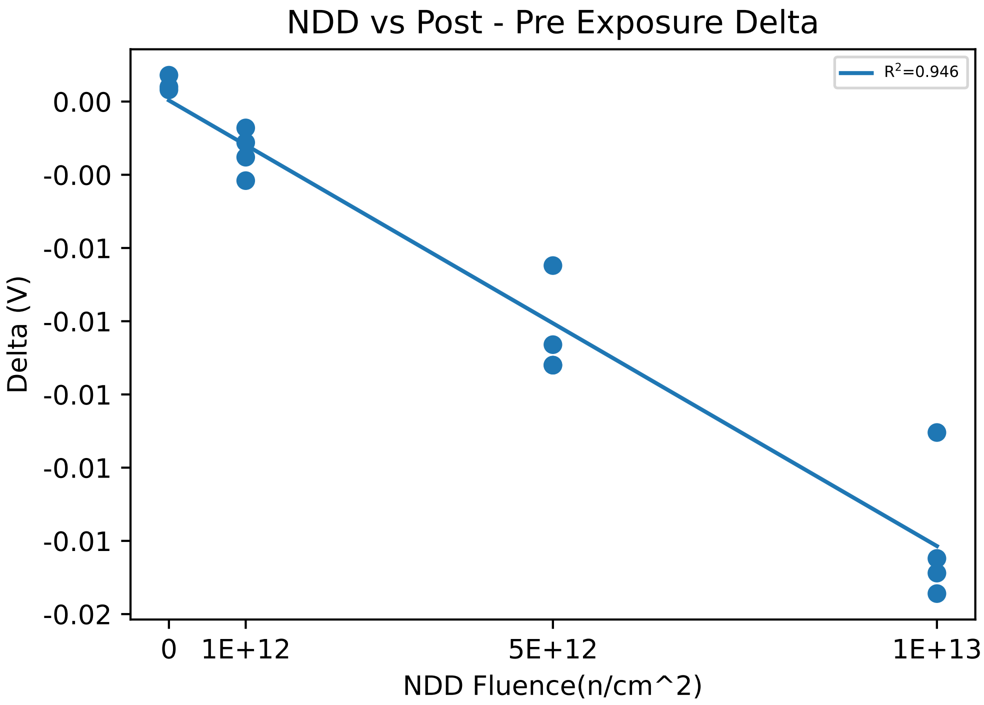
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.5877	3.5852	-0.0025
2	1e+12	NDD	3.5951	3.5936	-0.0015
3	1e+12	NDD	3.5906	3.5894	-0.0012
4	1e+12	NDD	3.6052	3.6058	0.0006
5	5e+12	NDD	3.5901	3.5833	-0.0068
6	5e+12	NDD	3.6022	3.5941	-0.0081
7	5e+12	NDD	3.5837	3.5774	-0.0063
8	5e+12	NDD	3.5935	3.5867	-0.0068
9	1e+13	NDD	3.5825	3.5694	-0.0131
10	1e+13	NDD	3.5924	3.5802	-0.0122
11	1e+13	NDD	3.5891	3.5783	-0.0108
12	1e+13	NDD	3.6003	3.5856	-0.0147
13	0	CORRELATION	3.5824	3.5815	-0.0009
14	0	CORRELATION	3.5751	3.5751	0
15	0	CORRELATION	3.5985	3.5981	-0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5751	3.5853	3.5985	0.011973	3.5751	3.5849	3.5981	0.011871	-0.0009	-0.00043333	0	0.00045092
1e+12	3.5877	3.5946	3.6052	0.007664	3.5852	3.5935	3.6058	0.0088882	-0.0025	-0.00115	0.0006	0.0012923
5e+12	3.5837	3.5924	3.6022	0.0077077	3.5774	3.5854	3.5941	0.0069711	-0.0081	-0.007	-0.0063	0.00077028
1e+13	3.5825	3.5911	3.6003	0.0074002	3.5694	3.5784	3.5856	0.0067352	-0.0147	-0.0127	-0.0108	0.001635

Device Test: 17.4 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_RISE





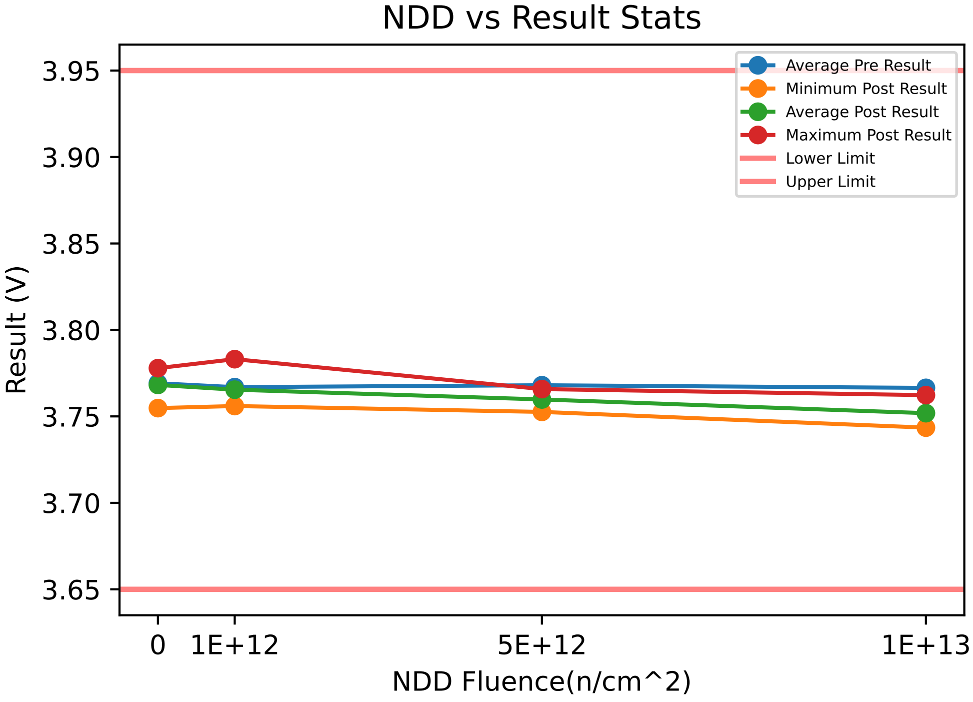
Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

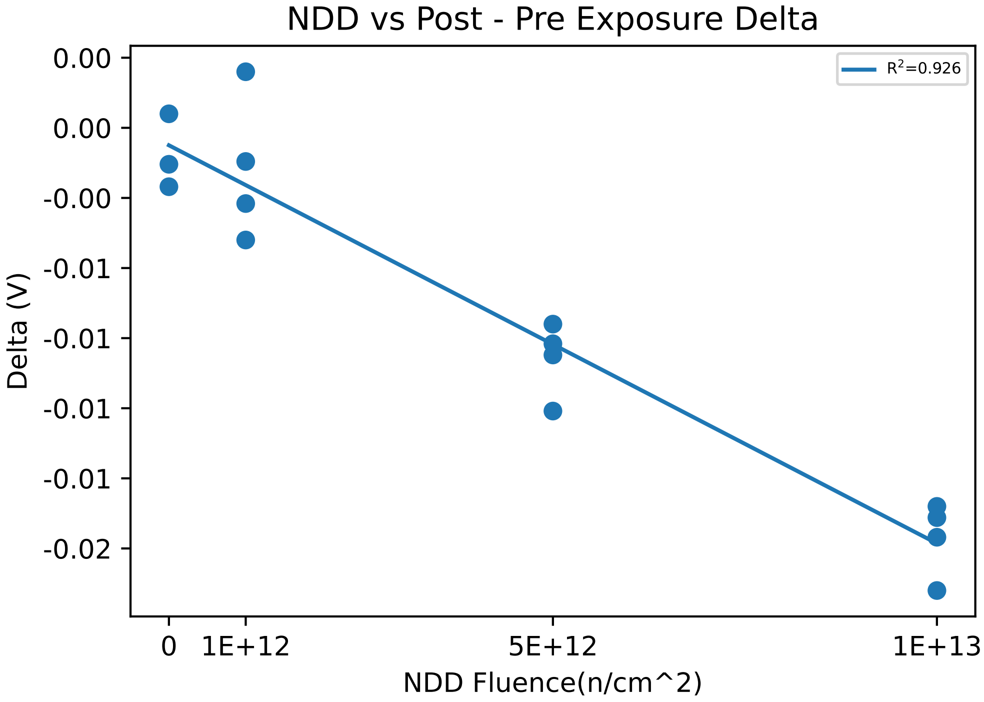
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.96	3.9573	-0.0027
2	1e+12	NDD	3.9672	3.9653	-0.0019
3	1e+12	NDD	3.9617	3.9608	-0.0009
4	1e+12	NDD	3.9865	3.9851	-0.0014
5	5e+12	NDD	3.9603	3.9547	-0.0056
6	5e+12	NDD	3.9695	3.9605	-0.009
7	5e+12	NDD	3.9684	3.9601	-0.0083
8	5e+12	NDD	3.9778	3.9688	-0.009
9	1e+13	NDD	3.9636	3.948	-0.0156
10	1e+13	NDD	3.9703	3.9542	-0.0161
11	1e+13	NDD	3.9635	3.9522	-0.0113
12	1e+13	NDD	3.9783	3.9615	-0.0168
13	0	CORRELATION	3.9712	3.9717	0.0005
14	0	CORRELATION	3.9566	3.9575	0.0009
15	0	CORRELATION	3.982	3.9824	0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9566	3.9699	3.982	0.012747	3.9575	3.9705	3.9824	0.012491	0.0004	0.0006	0.0009	0.00026458
1e+12	3.96	3.9688	3.9865	0.012161	3.9573	3.9671	3.9851	0.012423	-0.0027	-0.001725	-0.0009	0.00076757
5e+12	3.9603	3.969	3.9778	0.0071587	3.9547	3.961	3.9688	0.0058191	-0.009	-0.007975	-0.0056	0.0016174
1e+13	3.9635	3.9689	3.9783	0.0070135	3.948	3.954	3.9615	0.0056429	-0.0168	-0.01495	-0.0113	0.0024826

Device Test: 17.5 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_FALL





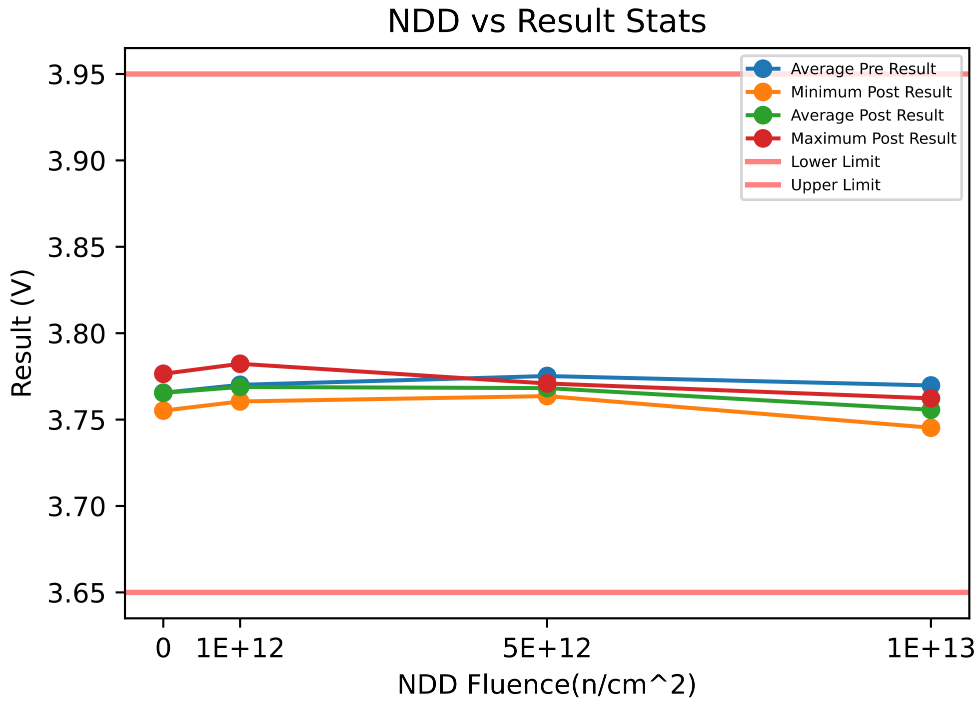
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

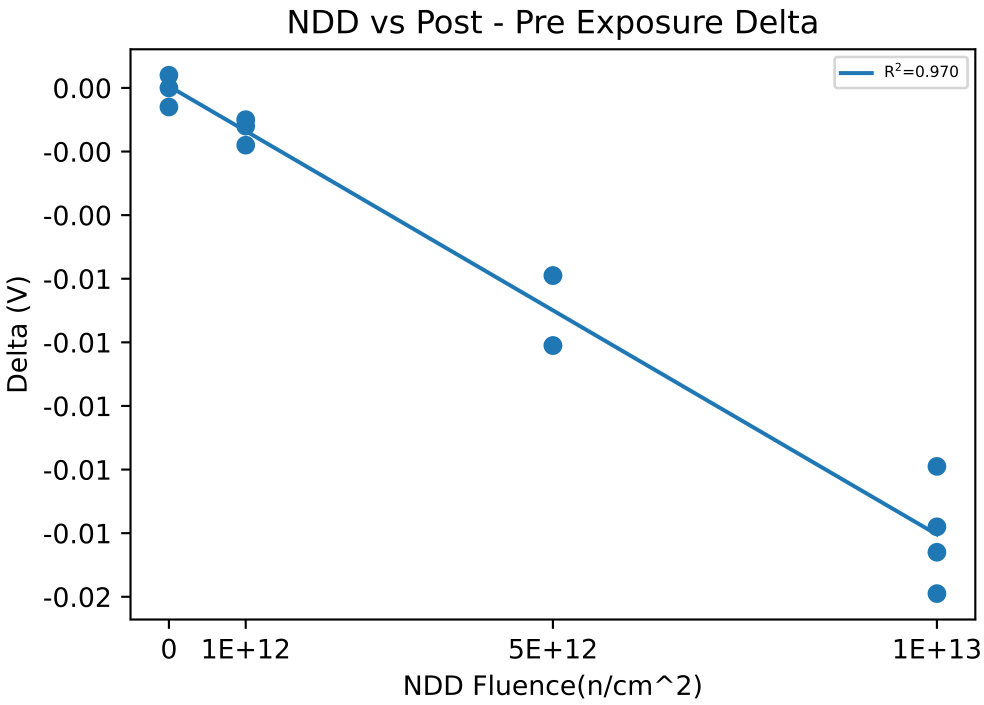
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7596	3.7569	-0.0027
2	1e+12	NDD	3.767	3.7658	-0.0012
3	1e+12	NDD	3.76	3.756	-0.004
4	1e+12	NDD	3.7811	3.7831	0.002
5	5e+12	NDD	3.7627	3.7526	-0.0101
6	5e+12	NDD	3.7669	3.7592	-0.0077
7	5e+12	NDD	3.7686	3.7616	-0.007
8	5e+12	NDD	3.7739	3.7658	-0.0081
9	1e+13	NDD	3.76	3.7435	-0.0165
10	1e+13	NDD	3.7639	3.75	-0.0139
11	1e+13	NDD	3.7652	3.7517	-0.0135
12	1e+13	NDD	3.7769	3.7623	-0.0146
13	0	CORRELATION	3.7714	3.7719	0.0005
14	0	CORRELATION	3.7561	3.7548	-0.0013
15	0	CORRELATION	3.78	3.7779	-0.0021

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7561	3.7692	3.78	0.012106	3.7548	3.7682	3.7779	0.011986	-0.0021	-0.00096667	0.0005	0.0013317
1e+12	3.7596	3.7669	3.7811	0.010042	3.756	3.7654	3.7831	0.01257	-0.004	-0.001475	0.002	0.0025838
5e+12	3.7627	3.768	3.7739	0.0046356	3.7526	3.7598	3.7658	0.0055209	-0.0101	-0.008225	-0.007	0.0013301
1e+13	3.76	3.7665	3.7769	0.0072769	3.7435	3.7519	3.7623	0.0077967	-0.0165	-0.014625	-0.0135	0.0013301

Device Test: 17.7 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_RISE





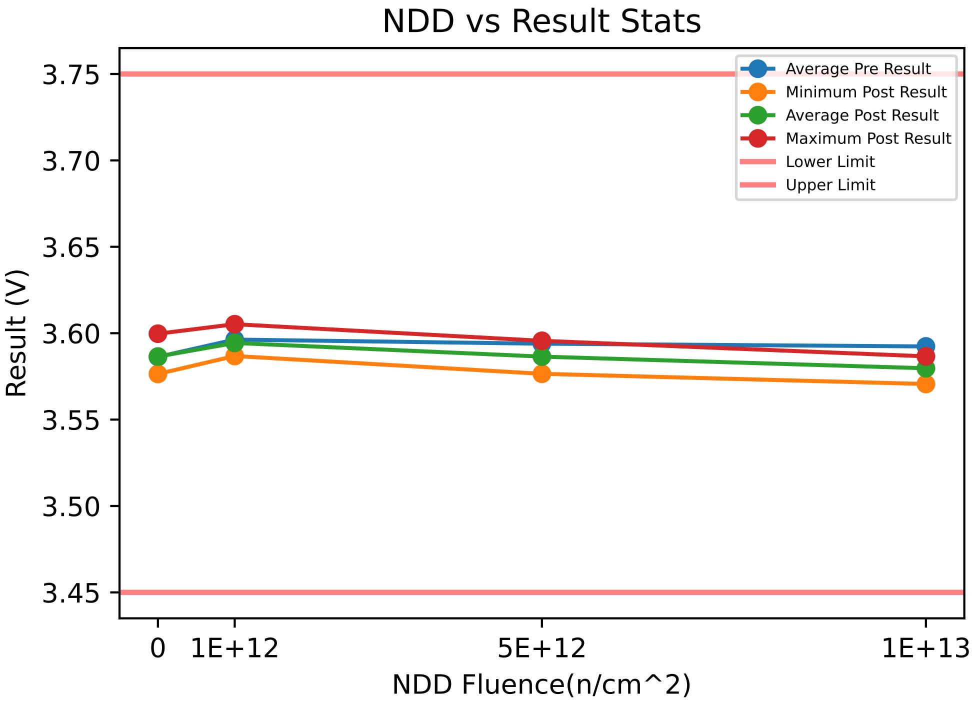
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

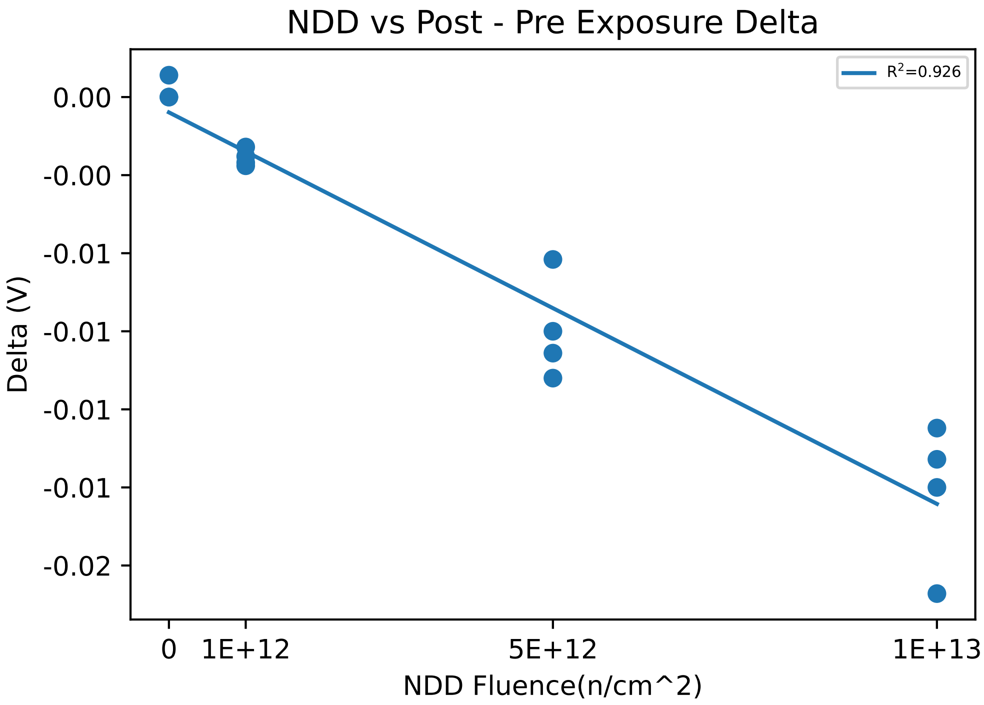
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7617	3.7605	-0.0012
2	1e+12	NDD	3.7628	3.7618	-0.001
3	1e+12	NDD	3.7727	3.7709	-0.0018
4	1e+12	NDD	3.7833	3.7823	-0.001
5	5e+12	NDD	3.7781	3.77	-0.0081
6	5e+12	NDD	3.7768	3.7709	-0.0059
7	5e+12	NDD	3.7695	3.7636	-0.0059
8	5e+12	NDD	3.7765	3.7684	-0.0081
9	1e+13	NDD	3.7599	3.7453	-0.0146
10	1e+13	NDD	3.7761	3.7623	-0.0138
11	1e+13	NDD	3.7656	3.7537	-0.0119
12	1e+13	NDD	3.7774	3.7615	-0.0159
13	0	CORRELATION	3.7558	3.7552	-0.0006
14	0	CORRELATION	3.7643	3.7647	0.0004
15	0	CORRELATION	3.7765	3.7765	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7558	3.7655	3.7765	0.010405	3.7552	3.7655	3.7765	0.010671	-0.0006	-6.6667e-05	0.0004	0.00050332
1e+12	3.7617	3.7701	3.7833	0.01008	3.7605	3.7689	3.7823	0.010075	-0.0018	-0.00125	-0.001	0.00037859
5e+12	3.7695	3.7752	3.7781	0.0038793	3.7636	3.7682	3.7709	0.0032521	-0.0081	-0.007	-0.0059	0.0012702
1e+13	3.7599	3.7698	3.7774	0.0084279	3.7453	3.7557	3.7623	0.0079448	-0.0159	-0.01405	-0.0119	0.0016743

Device Test: 17.8 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_FALL





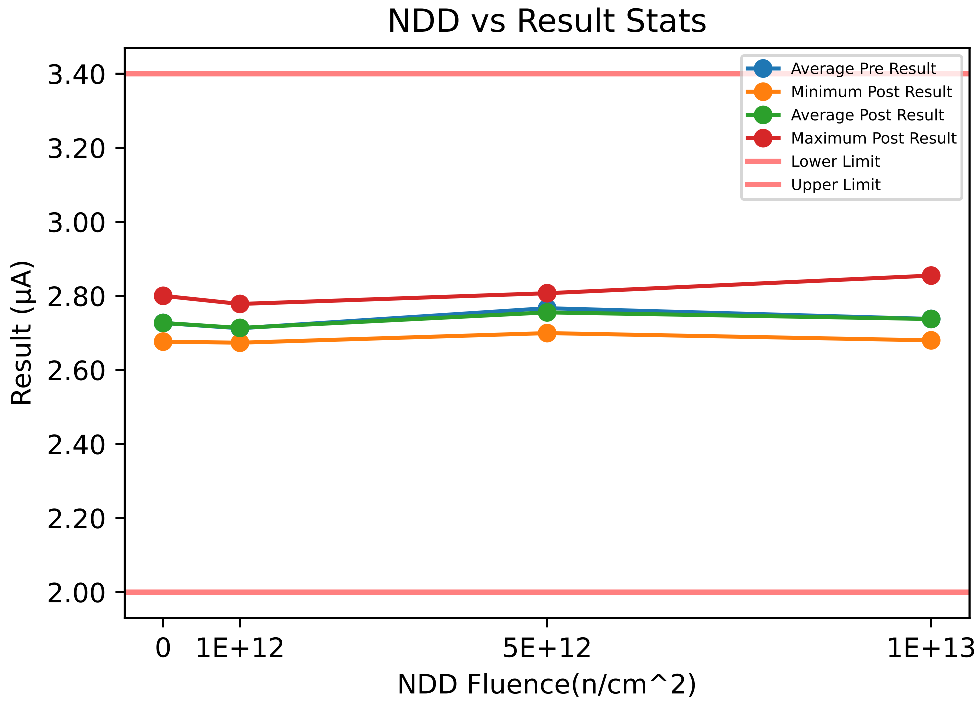
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

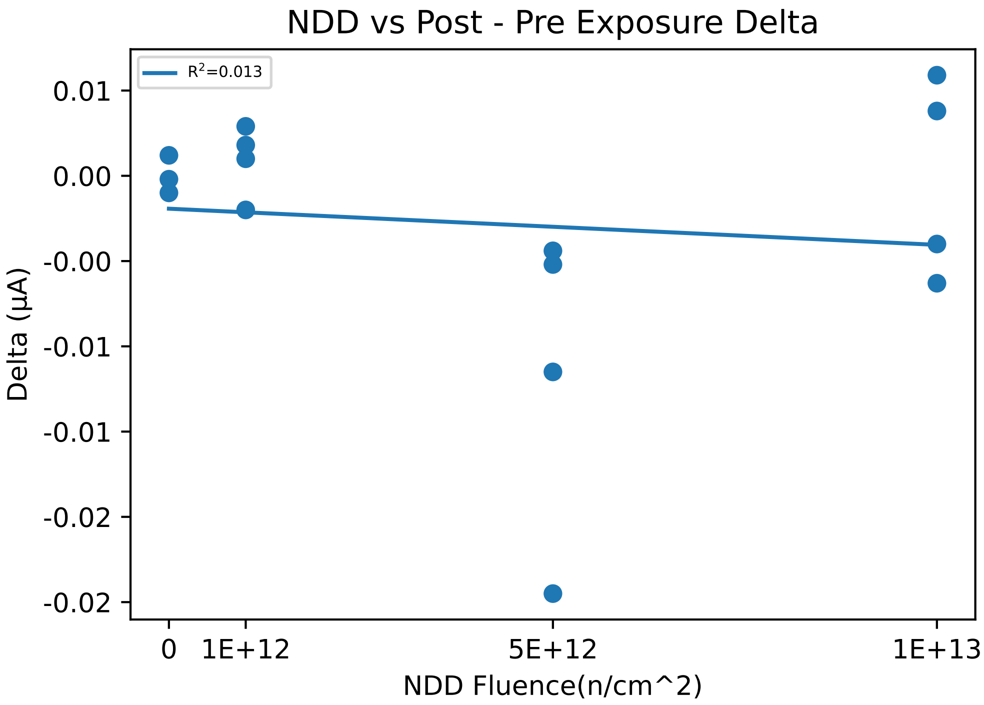
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.589	3.5868	-0.0022
2	1e+12	NDD	3.5966	3.5945	-0.0021
3	1e+12	NDD	3.5925	3.5909	-0.0016
4	1e+12	NDD	3.6071	3.6052	-0.0019
5	5e+12	NDD	3.591	3.5858	-0.0052
6	5e+12	NDD	3.6038	3.5956	-0.0082
7	5e+12	NDD	3.5855	3.5765	-0.009
8	5e+12	NDD	3.5954	3.5879	-0.0075
9	1e+13	NDD	3.5831	3.5706	-0.0125
10	1e+13	NDD	3.5937	3.5821	-0.0116
11	1e+13	NDD	3.5901	3.5795	-0.0106
12	1e+13	NDD	3.6025	3.5866	-0.0159
13	0	CORRELATION	3.5834	3.5834	0
14	0	CORRELATION	3.5757	3.5764	0.0007
15	0	CORRELATION	3.5997	3.5997	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5757	3.5863	3.5997	0.012254	3.5764	3.5865	3.5997	0.011955	0	0.00023333	0.0007	0.00040415
1e+12	3.589	3.5963	3.6071	0.0078413	3.5868	3.5943	3.6052	0.0078878	-0.0022	-0.00195	-0.0016	0.00026458
5e+12	3.5855	3.5939	3.6038	0.0077293	3.5765	3.5865	3.5956	0.0078581	-0.009	-0.007475	-0.0052	0.0016358
1e+13	3.5831	3.5924	3.6025	0.008072	3.5706	3.5797	3.5866	0.0067384	-0.0159	-0.01265	-0.0106	0.0023014

Device Test: 18.1 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/100kHz//@I_SS





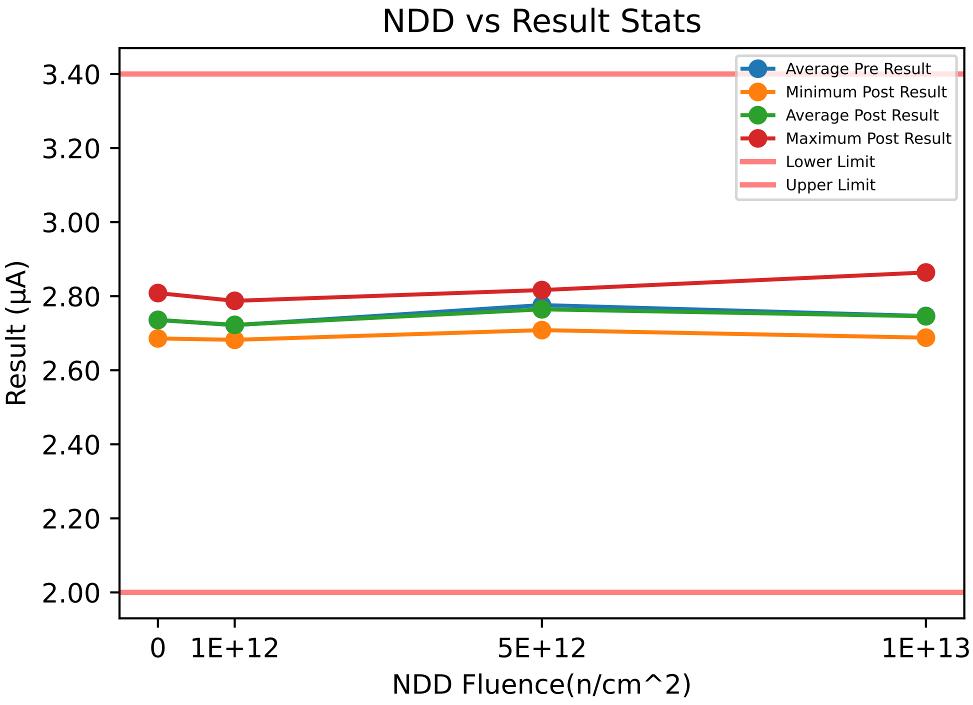
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

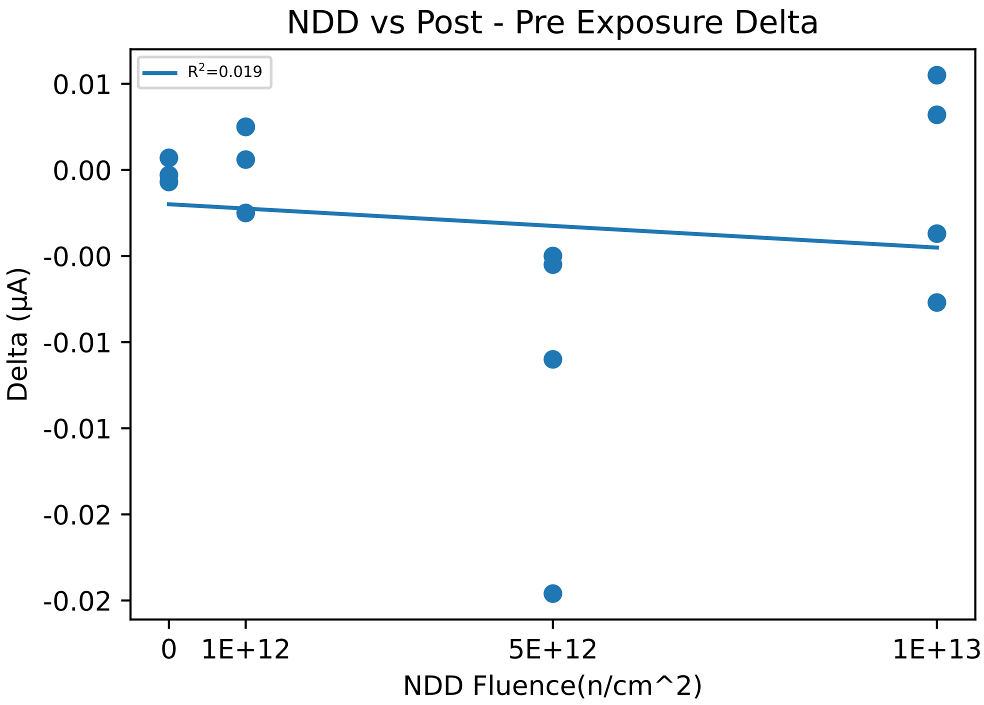
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7803	2.7783	-0.002
2	1e+12	NDD	2.6707	2.6736	0.0029
3	1e+12	NDD	2.7222	2.724	0.0018
4	1e+12	NDD	2.6774	2.6784	0.001
5	5e+12	NDD	2.8125	2.8073	-0.0052
6	5e+12	NDD	2.7817	2.7702	-0.0115
7	5e+12	NDD	2.7694	2.7449	-0.0245
8	5e+12	NDD	2.704	2.6996	-0.0044
9	1e+13	NDD	2.6798	2.6836	0.0038
10	1e+13	NDD	2.6741	2.68	0.0059
11	1e+13	NDD	2.7385	2.7322	-0.0063
12	1e+13	NDD	2.8589	2.8549	-0.004
13	0	CORRELATION	2.7051	2.7041	-0.001
14	0	CORRELATION	2.799	2.8002	0.0012
15	0	CORRELATION	2.6768	2.6766	-0.0002

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6768	2.727	2.799	0.063967	2.6766	2.727	2.8002	0.064895	-0.001	0	0.0012	0.0011136
1e+12	2.6707	2.7127	2.7803	0.050564	2.6736	2.7136	2.7783	0.048762	-0.002	0.000925	0.0029	0.0020998
5e+12	2.704	2.7669	2.8125	0.045684	2.6996	2.7555	2.8073	0.045227	-0.0245	-0.0114	-0.0044	0.0092926
1e+13	2.6741	2.7378	2.8589	0.085805	2.68	2.7377	2.8549	0.081695	-0.0063	-0.00015	0.0059	0.0059119

Device Test: 18.13 CURRENT|SS_0p3V/SS/14/14/0/1000/5/100kHz//@I_SS





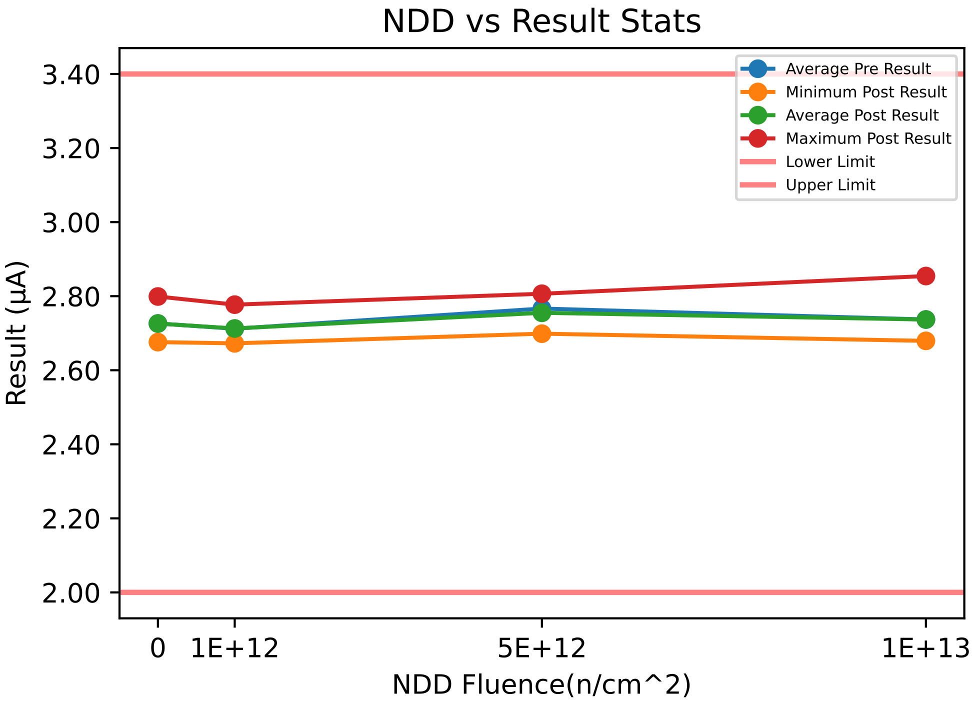
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (μA))

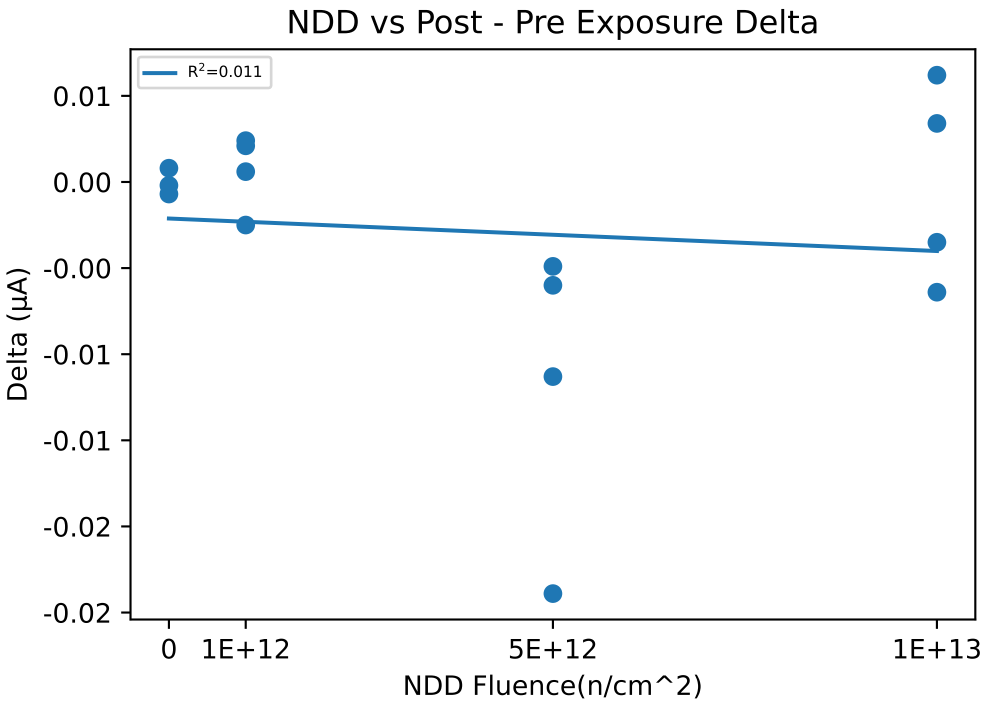
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7899	2.7874	-0.0025
2	1e+12	NDD	2.6796	2.6821	0.0025
3	1e+12	NDD	2.7308	2.7333	0.0025
4	1e+12	NDD	2.6865	2.6871	0.0006
5	5e+12	NDD	2.8215	2.8165	-0.005
6	5e+12	NDD	2.7904	2.7794	-0.011
7	5e+12	NDD	2.7782	2.7536	-0.0246
8	5e+12	NDD	2.7138	2.7083	-0.0055
9	1e+13	NDD	2.6882	2.6914	0.0032
10	1e+13	NDD	2.6824	2.6879	0.0055
11	1e+13	NDD	2.7473	2.7396	-0.0077
12	1e+13	NDD	2.8677	2.864	-0.0037
13	0	CORRELATION	2.7136	2.7129	-0.0007
14	0	CORRELATION	2.8077	2.8084	0.0007
15	0	CORRELATION	2.6861	2.6858	-0.0003

Test Statistics (μA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6861	2.7358	2.8077	0.063767	2.6858	2.7357	2.8084	0.064402	-0.0007	-0.0001	0.0007	0.00072111
1e+12	2.6796	2.7217	2.7899	0.050812	2.6821	2.7225	2.7874	0.049037	-0.0025	0.000775	0.0025	0.0023599
5e+12	2.7138	2.776	2.8215	0.045282	2.7083	2.7645	2.8165	0.045473	-0.0246	-0.011525	-0.005	0.0091307
1e+13	2.6824	2.7464	2.8677	0.086019	2.6879	2.7457	2.864	0.082303	-0.0077	-0.000675	0.0055	0.0061005

Device Test: 18.17 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/500kHz//@I_SS





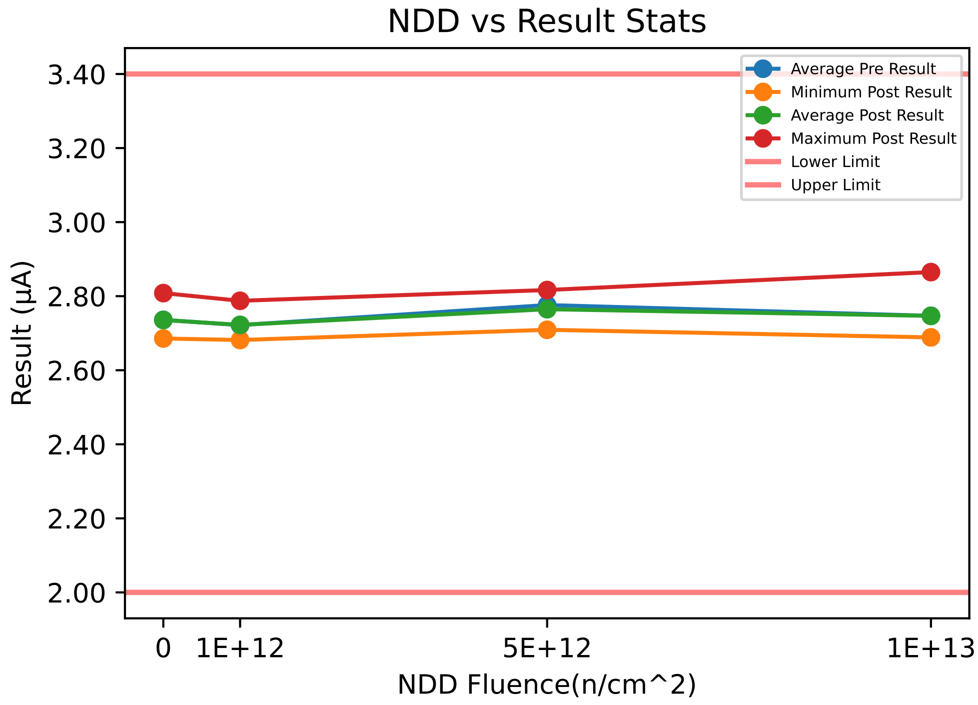
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

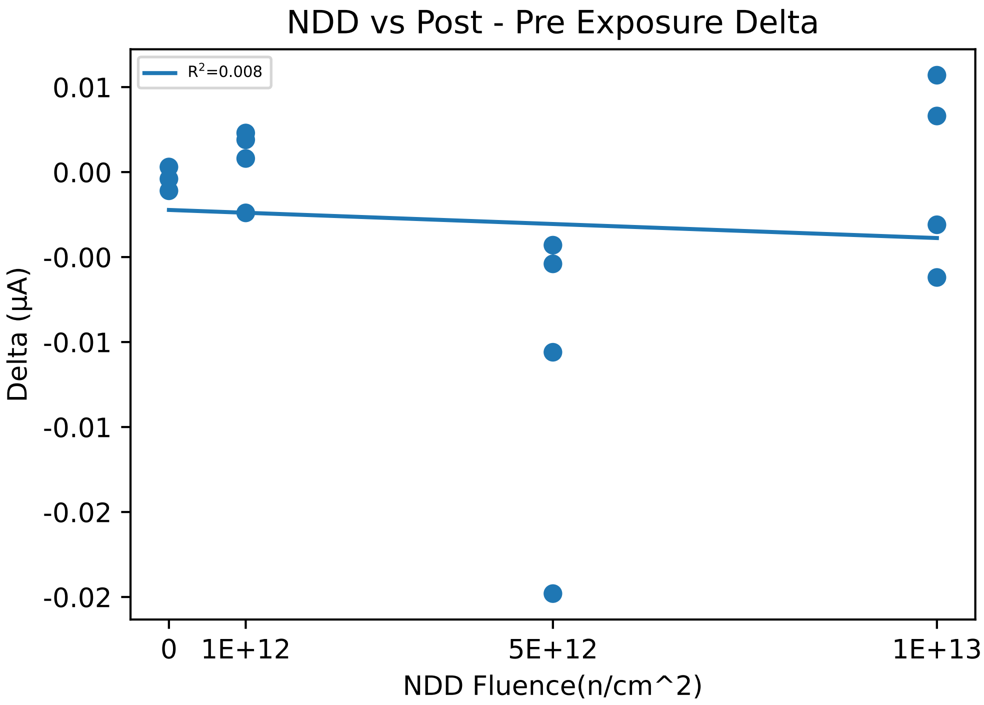
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7796	2.7771	-0.0025
2	1e+12	NDD	2.6702	2.6726	0.0024
3	1e+12	NDD	2.7218	2.7239	0.0021
4	1e+12	NDD	2.6768	2.6774	0.0006
5	5e+12	NDD	2.8125	2.8065	-0.006
6	5e+12	NDD	2.7812	2.7699	-0.0113
7	5e+12	NDD	2.7689	2.745	-0.0239
8	5e+12	NDD	2.7036	2.6987	-0.0049
9	1e+13	NDD	2.6795	2.6829	0.0034
10	1e+13	NDD	2.6731	2.6793	0.0062
11	1e+13	NDD	2.7375	2.7311	-0.0064
12	1e+13	NDD	2.8579	2.8544	-0.0035
13	0	CORRELATION	2.7041	2.7034	-0.0007
14	0	CORRELATION	2.7983	2.7991	0.0008
15	0	CORRELATION	2.6761	2.6759	-0.0002

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6761	2.7262	2.7983	0.064019	2.6759	2.7261	2.7991	0.06467	-0.0007	-3.3333e-05	0.0008	0.00076376
1e+12	2.6702	2.7121	2.7796	0.050504	2.6726	2.7127	2.7771	0.04874	-0.0025	0.00065	0.0024	0.0022428
5e+12	2.7036	2.7666	2.8125	0.045805	2.6987	2.755	2.8065	0.045255	-0.0239	-0.011525	-0.0049	0.0087103
1e+13	2.6731	2.737	2.8579	0.085648	2.6793	2.7369	2.8544	0.0818	-0.0064	-7.5e-05	0.0062	0.0058648

Device Test: 18.21 CURRENT|SS_0p3V/SS/5/5/0/1000/5/500kHz//@I_SS





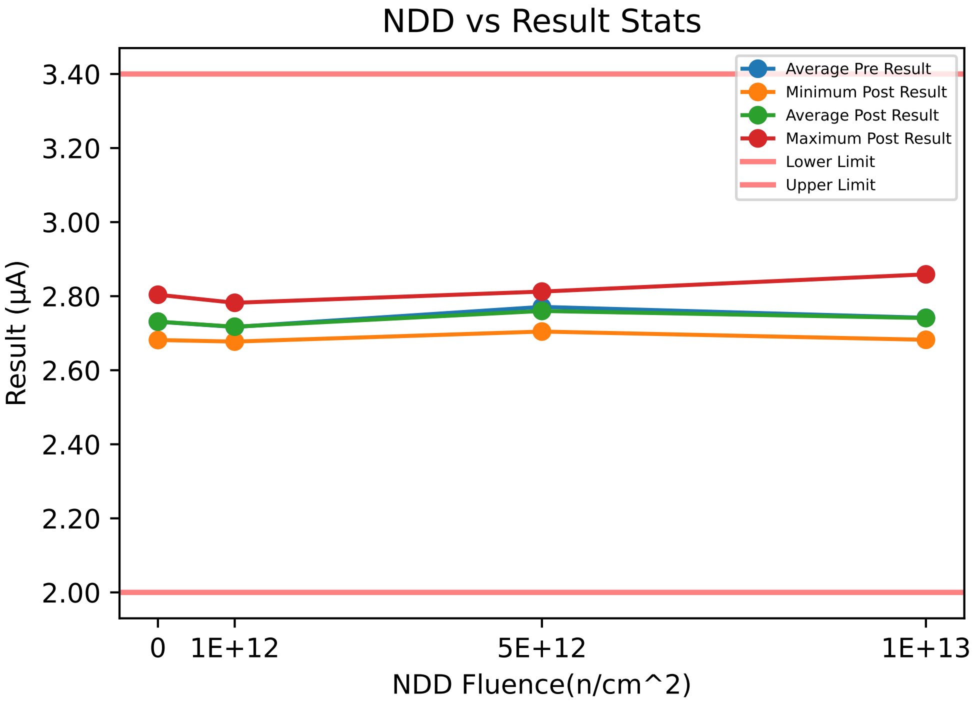
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

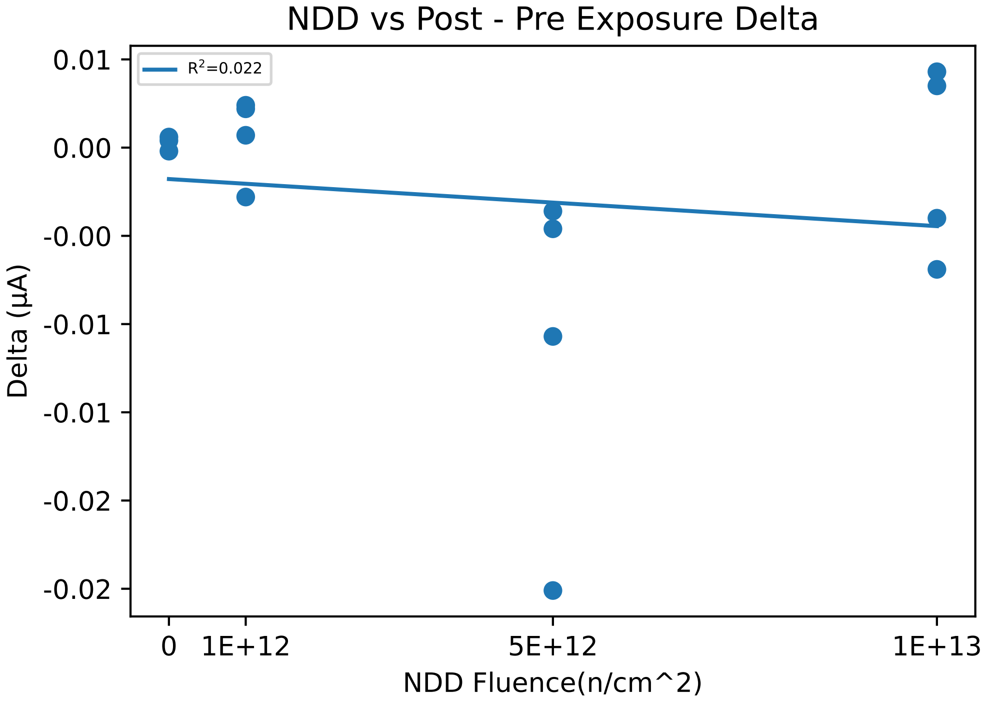
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7899	2.7875	-0.0024
2	1e+12	NDD	2.6797	2.6816	0.0019
3	1e+12	NDD	2.7312	2.7335	0.0023
4	1e+12	NDD	2.6864	2.6872	0.0008
5	5e+12	NDD	2.822	2.8166	-0.0054
6	5e+12	NDD	2.7899	2.7793	-0.0106
7	5e+12	NDD	2.7788	2.754	-0.0248
8	5e+12	NDD	2.7135	2.7092	-0.0043
9	1e+13	NDD	2.6891	2.6924	0.0033
10	1e+13	NDD	2.683	2.6887	0.0057
11	1e+13	NDD	2.7474	2.7412	-0.0062
12	1e+13	NDD	2.8681	2.865	-0.0031
13	0	CORRELATION	2.714	2.7129	-0.0011
14	0	CORRELATION	2.808	2.8083	0.0003
15	0	CORRELATION	2.6861	2.6857	-0.0004

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6861	2.736	2.808	0.063867	2.6857	2.7356	2.8083	0.064384	-0.0011	-0.0004	0.0003	0.0007
1e+12	2.6797	2.7218	2.7899	0.050832	2.6816	2.7224	2.7875	0.04921	-0.0024	0.00065	0.0023	0.0021299
5e+12	2.7135	2.776	2.822	0.045546	2.7092	2.7648	2.8166	0.045098	-0.0248	-0.011275	-0.0043	0.009426
1e+13	2.683	2.7469	2.8681	0.085856	2.6887	2.7468	2.865	0.082336	-0.0062	-7.5e-05	0.0057	0.0055199

Device Test: 18.25 CURRENT|SS_0p3V/SS/12/12/0/1000/5/500kHz//@I_SS





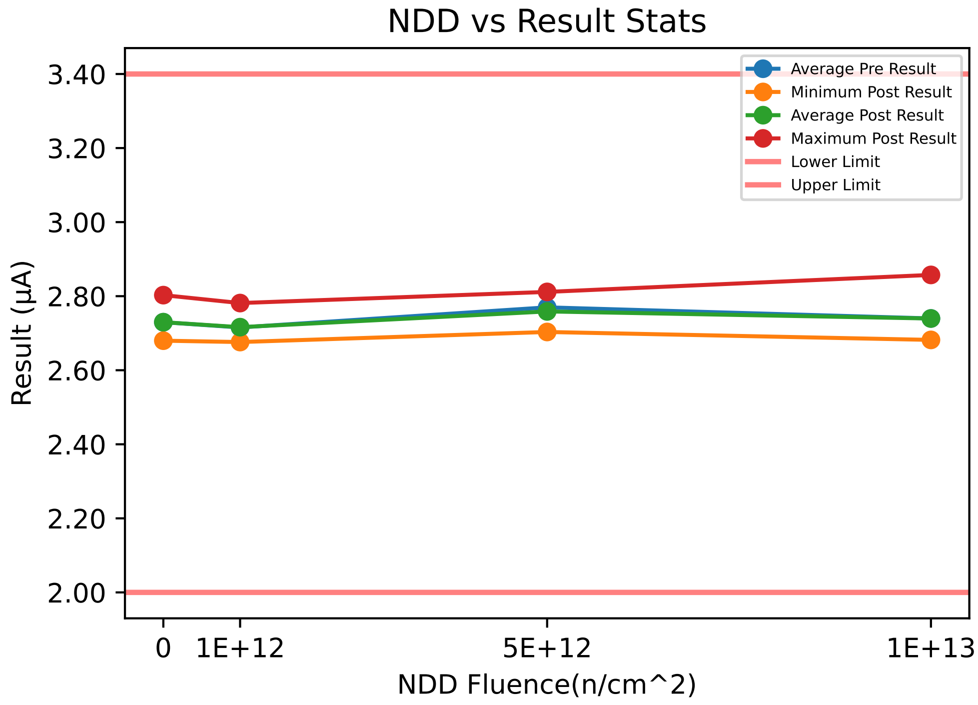
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

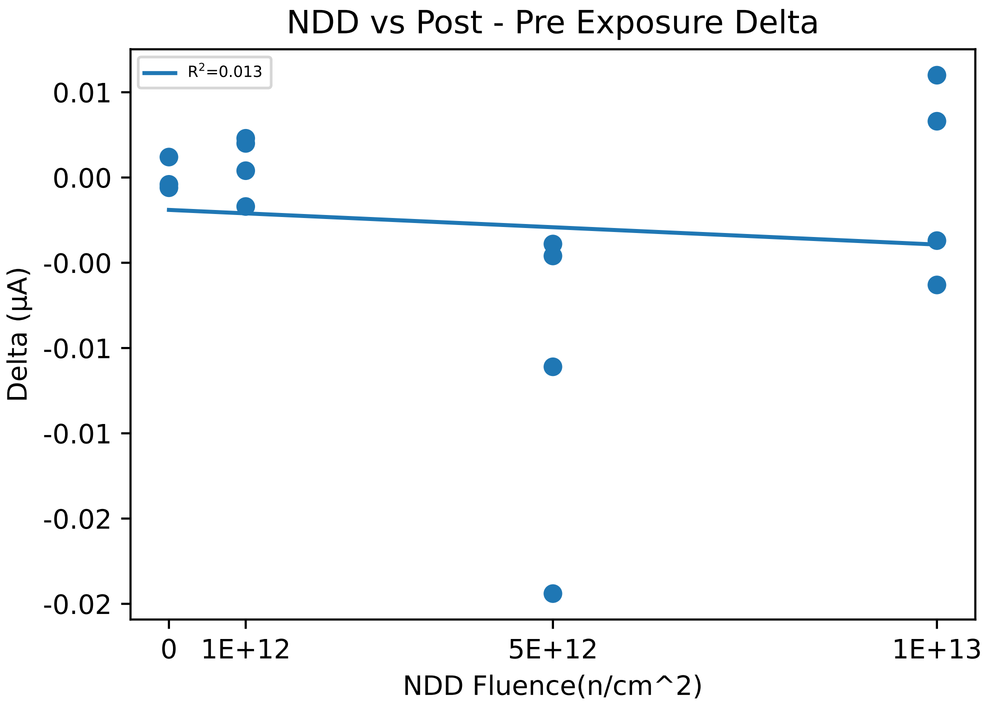
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7849	2.7821	-0.0028
2	1e+12	NDD	2.6749	2.6773	0.0024
3	1e+12	NDD	2.726	2.7282	0.0022
4	1e+12	NDD	2.6817	2.6824	0.0007
5	5e+12	NDD	2.817	2.8124	-0.0046
6	5e+12	NDD	2.7853	2.7746	-0.0107
7	5e+12	NDD	2.7738	2.7487	-0.0251
8	5e+12	NDD	2.7081	2.7045	-0.0036
9	1e+13	NDD	2.6829	2.6864	0.0035
10	1e+13	NDD	2.6779	2.6822	0.0043
11	1e+13	NDD	2.7428	2.7359	-0.0069
12	1e+13	NDD	2.8629	2.8589	-0.004
13	0	CORRELATION	2.7085	2.7083	-0.0002
14	0	CORRELATION	2.8033	2.8039	0.0006
15	0	CORRELATION	2.6812	2.6816	0.0004

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6812	2.731	2.8033	0.064084	2.6816	2.7313	2.8039	0.064303	-0.0002	0.00026667	0.0006	0.00041633
1e+12	2.6749	2.7169	2.7849	0.050695	2.6773	2.7175	2.7821	0.048771	-0.0028	0.000625	0.0024	0.0024061
5e+12	2.7081	2.771	2.817	0.04577	2.7045	2.76	2.8124	0.045339	-0.0251	-0.011	-0.0036	0.0099099
1e+13	2.6779	2.7416	2.8629	0.086059	2.6822	2.7409	2.8589	0.082391	-0.0069	-0.000775	0.0043	0.0055362

Device Test: 18.29 CURRENT|SS_0p3V/SS/14/14/0/1000/5/500kHz//@I_SS


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

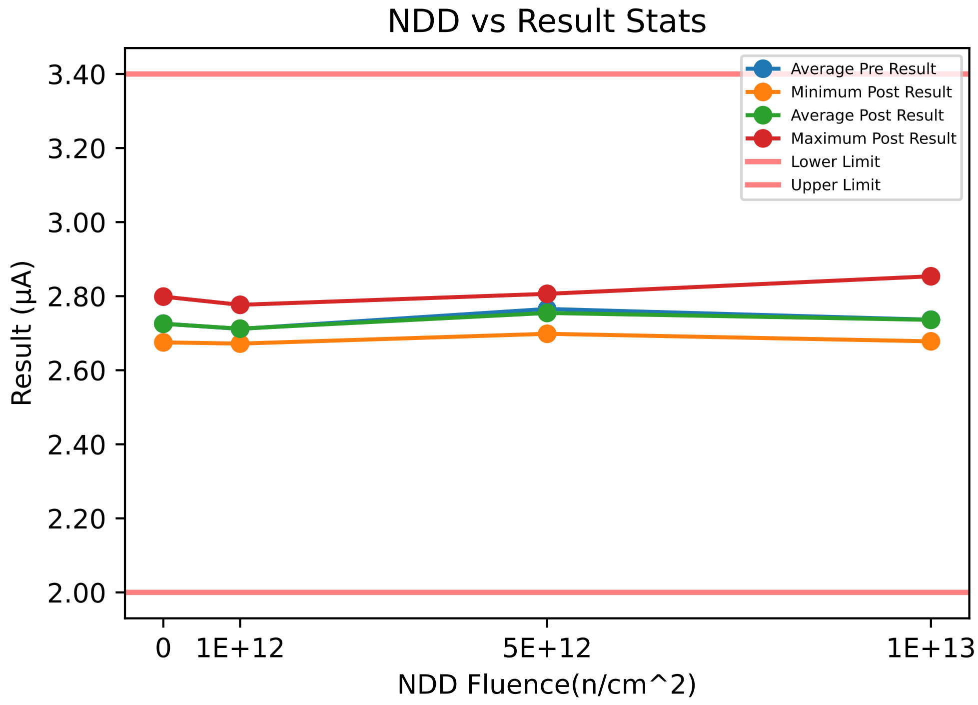
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

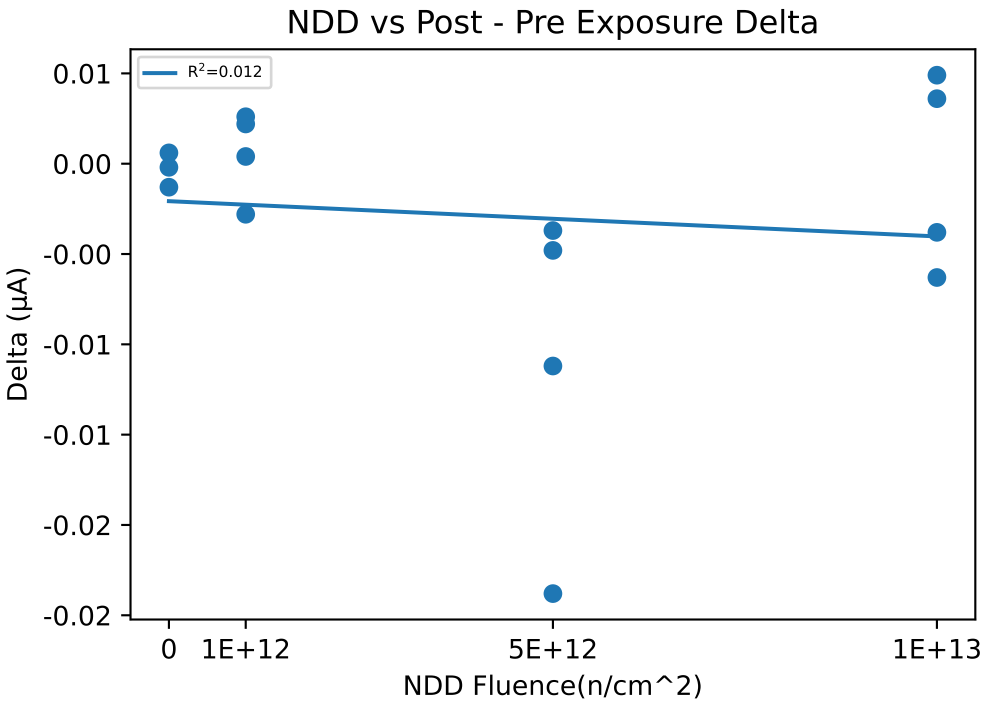
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7831	2.7814	-0.0017
2	1e+12	NDD	2.6738	2.6761	0.0023
3	1e+12	NDD	2.7248	2.7268	0.002
4	1e+12	NDD	2.6804	2.6808	0.0004
5	5e+12	NDD	2.8161	2.8115	-0.0046
6	5e+12	NDD	2.7837	2.7726	-0.0111
7	5e+12	NDD	2.7721	2.7477	-0.0244
8	5e+12	NDD	2.7072	2.7033	-0.0039
9	1e+13	NDD	2.6816	2.6849	0.0033
10	1e+13	NDD	2.6759	2.6819	0.006
11	1e+13	NDD	2.7408	2.7345	-0.0063
12	1e+13	NDD	2.8611	2.8574	-0.0037
13	0	CORRELATION	2.7072	2.7066	-0.0006
14	0	CORRELATION	2.8016	2.8028	0.0012
15	0	CORRELATION	2.6802	2.6798	-0.0004

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6802	2.7297	2.8016	0.063742	2.6798	2.7297	2.8028	0.064681	-0.0006	6.6667e-05	0.0012	0.00098658
1e+12	2.6738	2.7155	2.7831	0.050422	2.6761	2.7163	2.7814	0.049073	-0.0017	0.00075	0.0023	0.0018339
5e+12	2.7072	2.7698	2.8161	0.045684	2.7033	2.7588	2.8115	0.045355	-0.0244	-0.011	-0.0039	0.0095033
1e+13	2.6759	2.7399	2.8611	0.085994	2.6819	2.7397	2.8574	0.082106	-0.0063	-0.000175	0.006	0.0057778

Device Test: 18.33 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/1MHz//@I_SS





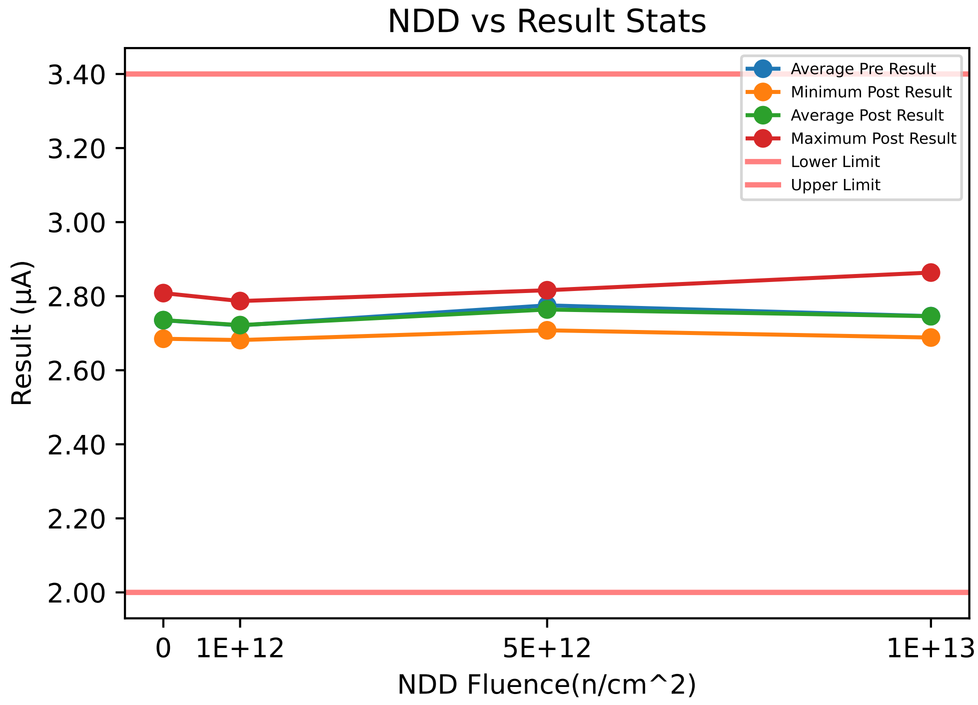
Test Results (Lower Limit = 2.0,
Upper Limit = 3.4 (µA))

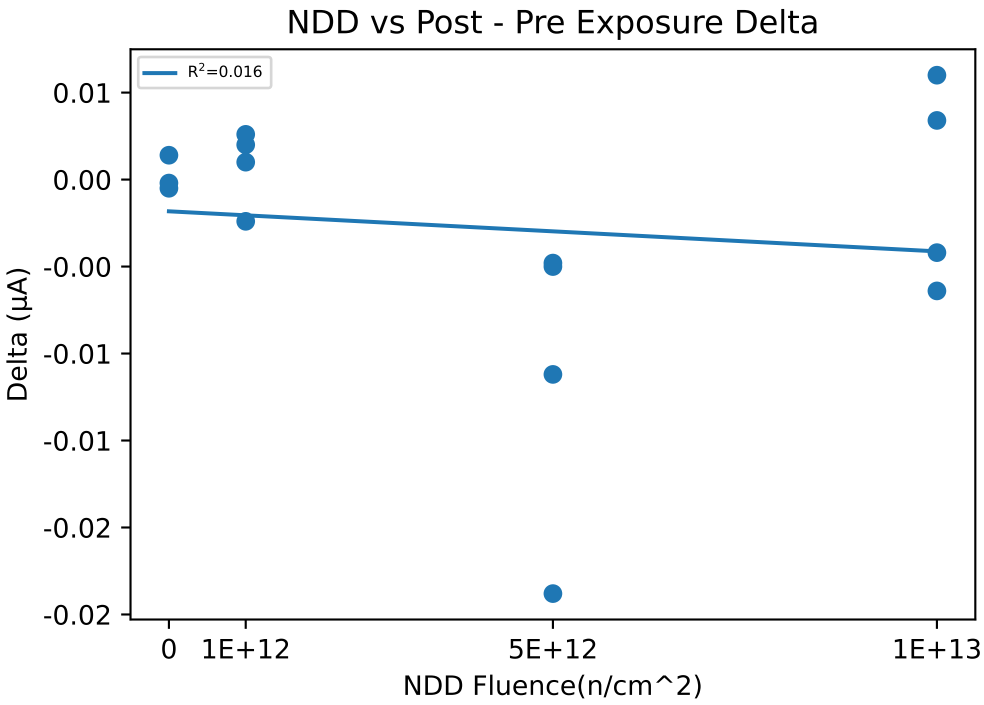
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7794	2.7766	-0.0028
2	1e+12	NDD	2.6697	2.6719	0.0022
3	1e+12	NDD	2.7208	2.7234	0.0026
4	1e+12	NDD	2.6764	2.6768	0.0004
5	5e+12	NDD	2.8111	2.8063	-0.0048
6	5e+12	NDD	2.7804	2.7692	-0.0112
7	5e+12	NDD	2.7684	2.7446	-0.0238
8	5e+12	NDD	2.7021	2.6984	-0.0037
9	1e+13	NDD	2.6784	2.682	0.0036
10	1e+13	NDD	2.6731	2.678	0.0049
11	1e+13	NDD	2.7366	2.7303	-0.0063
12	1e+13	NDD	2.8575	2.8537	-0.0038
13	0	CORRELATION	2.7037	2.7024	-0.0013
14	0	CORRELATION	2.7982	2.7988	0.0006
15	0	CORRELATION	2.6754	2.6752	-0.0002

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6754	2.7258	2.7982	0.064305	2.6752	2.7255	2.7988	0.064948	-0.0013	-0.0003	0.0006	0.00095394
1e+12	2.6697	2.7116	2.7794	0.050584	2.6719	2.7122	2.7766	0.04882	-0.0028	0.0006	0.0026	0.0024604
5e+12	2.7021	2.7655	2.8111	0.045932	2.6984	2.7546	2.8063	0.045257	-0.0238	-0.010875	-0.0037	0.0092294
1e+13	2.6731	2.7364	2.8575	0.085705	2.678	2.736	2.8537	0.081987	-0.0063	-0.0004	0.0049	0.0054912

Device Test: 18.37 CURRENT|SS_0p3V/SS/5/5/0/1000/5/1MHz//@I_SS





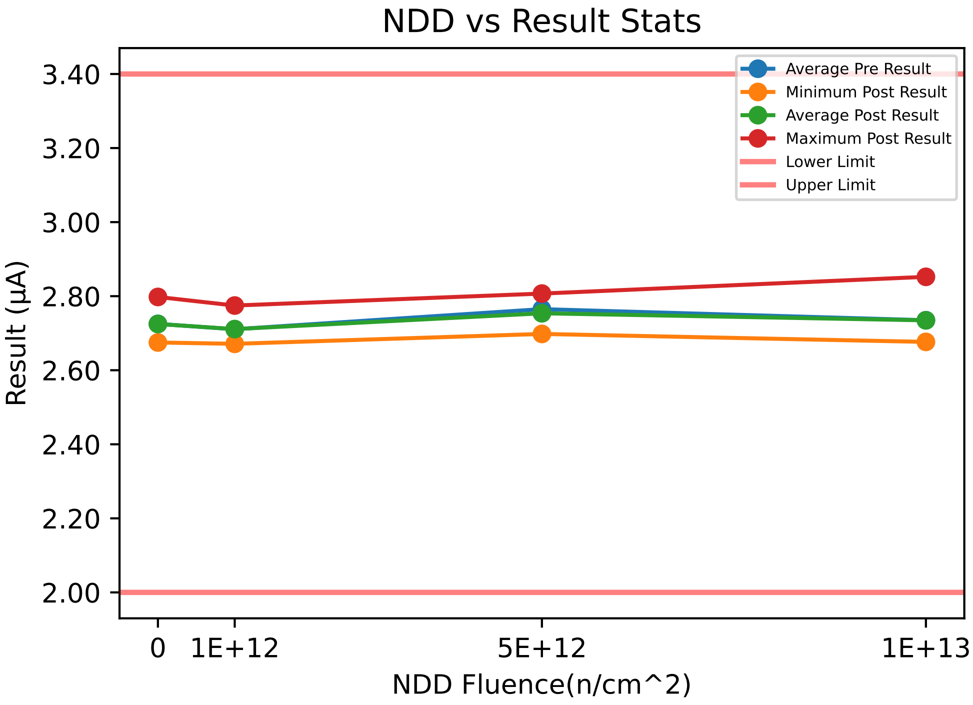
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

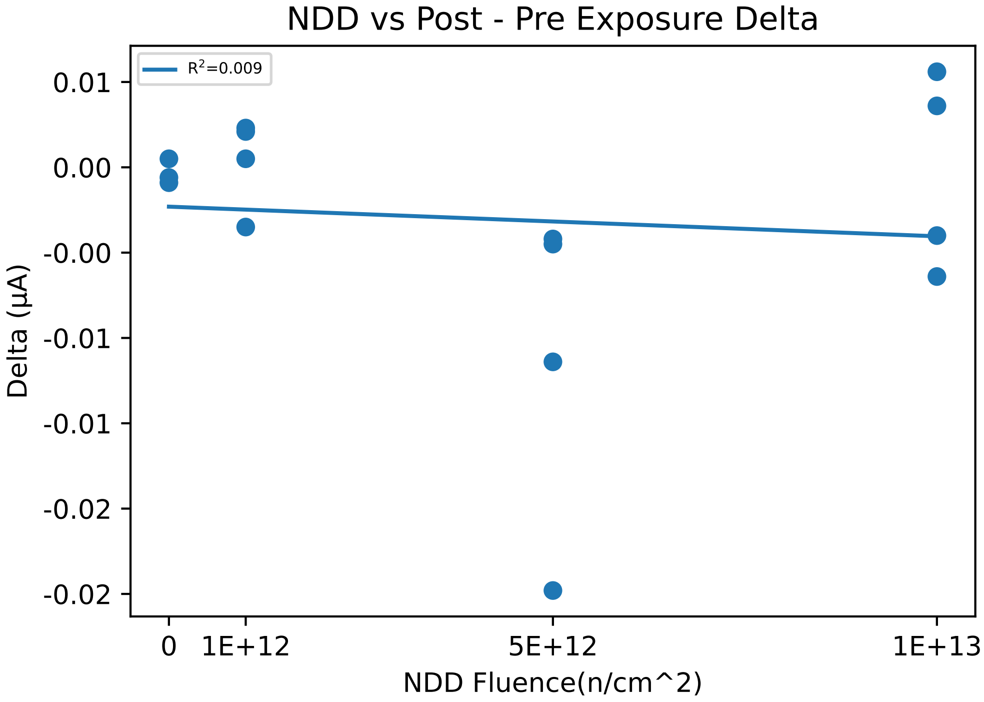
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7892	2.7868	-0.0024
2	1e+12	NDD	2.6795	2.6815	0.002
3	1e+12	NDD	2.7299	2.7325	0.0026
4	1e+12	NDD	2.6856	2.6866	0.001
5	5e+12	NDD	2.821	2.816	-0.005
6	5e+12	NDD	2.7896	2.7784	-0.0112
7	5e+12	NDD	2.7775	2.7537	-0.0238
8	5e+12	NDD	2.7126	2.7078	-0.0048
9	1e+13	NDD	2.6878	2.6912	0.0034
10	1e+13	NDD	2.6823	2.6883	0.006
11	1e+13	NDD	2.7463	2.7399	-0.0064
12	1e+13	NDD	2.868	2.8638	-0.0042
13	0	CORRELATION	2.7128	2.7126	-0.0002
14	0	CORRELATION	2.8069	2.8083	0.0014
15	0	CORRELATION	2.6855	2.685	-0.0005

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6855	2.7351	2.8069	0.063689	2.685	2.7353	2.8083	0.064709	-0.0005	0.00023333	0.0014	0.0010214
1e+12	2.6795	2.721	2.7892	0.050682	2.6815	2.7218	2.7868	0.048999	-0.0024	0.0008	0.0026	0.0022331
5e+12	2.7126	2.7752	2.821	0.045567	2.7078	2.764	2.816	0.045372	-0.0238	-0.0112	-0.0048	0.0089099
1e+13	2.6823	2.7461	2.868	0.086273	2.6883	2.7458	2.8638	0.082151	-0.0064	-0.0003	0.006	0.0059386

Device Test: 18.41 CURRENT|SS_0p3V/SS/12/12/0/1000/5/1MHz//@I_SS





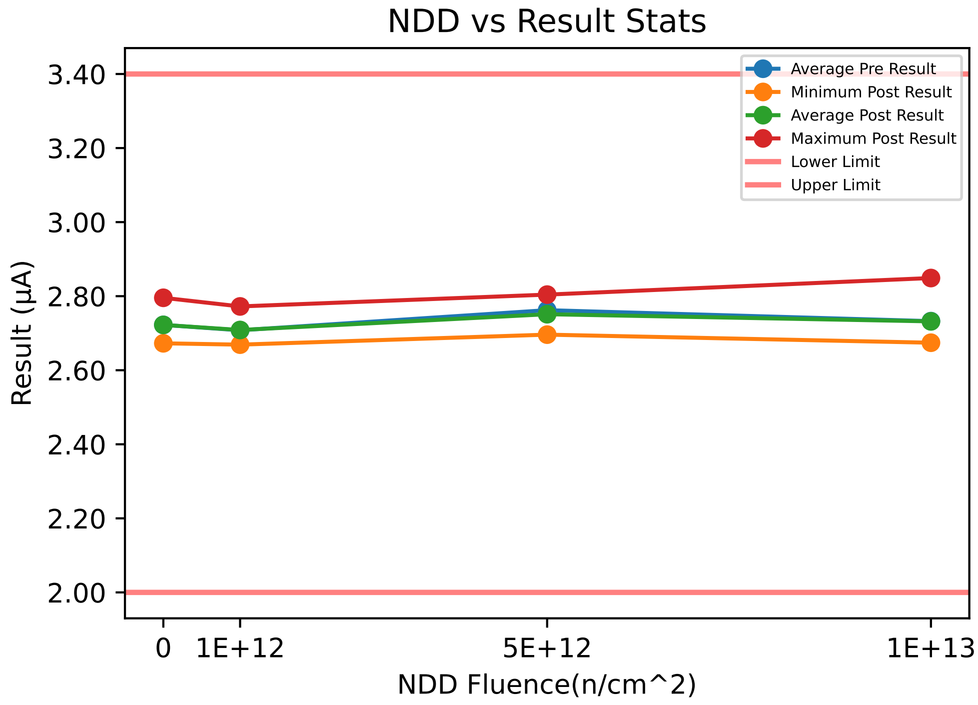
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

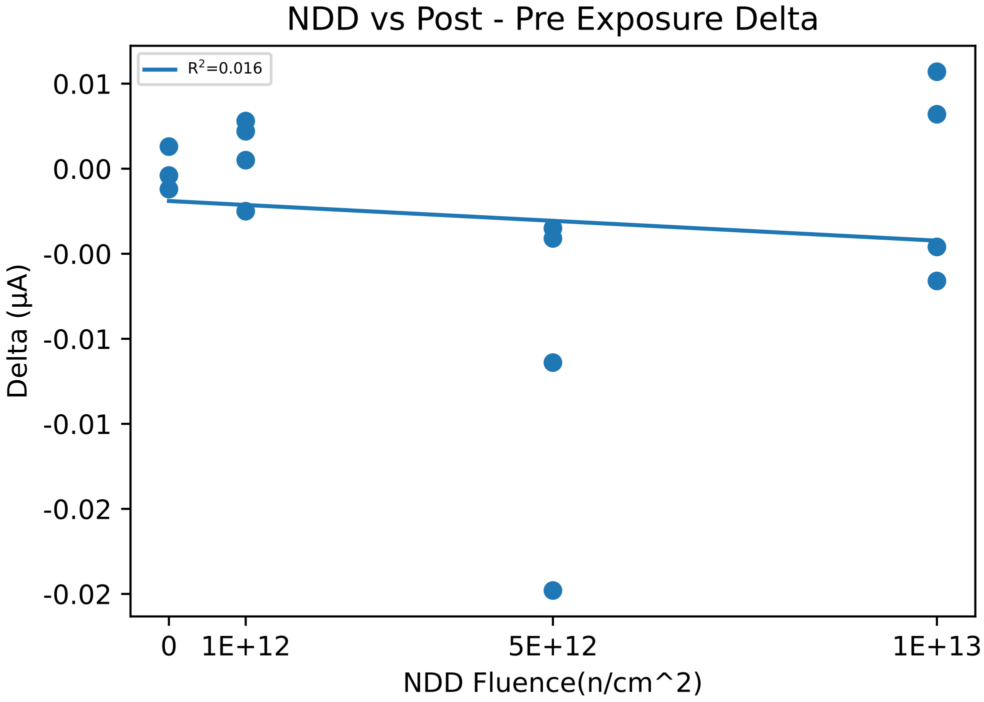
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7782	2.7747	-0.0035
2	1e+12	NDD	2.6692	2.6713	0.0021
3	1e+12	NDD	2.72	2.7223	0.0023
4	1e+12	NDD	2.6754	2.6759	0.0005
5	5e+12	NDD	2.8115	2.807	-0.0045
6	5e+12	NDD	2.7787	2.7673	-0.0114
7	5e+12	NDD	2.7675	2.7427	-0.0248
8	5e+12	NDD	2.7022	2.698	-0.0042
9	1e+13	NDD	2.6763	2.6799	0.0036
10	1e+13	NDD	2.6709	2.6765	0.0056
11	1e+13	NDD	2.7367	2.7303	-0.0064
12	1e+13	NDD	2.8562	2.8522	-0.004
13	0	CORRELATION	2.7026	2.7017	-0.0009
14	0	CORRELATION	2.7974	2.7979	0.0005
15	0	CORRELATION	2.6755	2.6749	-0.0006

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6755	2.7252	2.7974	0.064007	2.6749	2.7248	2.7979	0.064681	-0.0009	-0.00033333	0.0005	0.00073711
1e+12	2.6692	2.7107	2.7782	0.050369	2.6713	2.7111	2.7747	0.048282	-0.0035	0.00035	0.0023	0.0026901
5e+12	2.7022	2.765	2.8115	0.045826	2.698	2.7538	2.807	0.045641	-0.0248	-0.011225	-0.0042	0.0096417
1e+13	2.6709	2.735	2.8562	0.086114	2.6765	2.7347	2.8522	0.082089	-0.0064	-0.0003	0.0056	0.0058

Device Test: 18.45 CURRENT|SS_0p3V/SS/14/14/0/1000/5/1MHz//@I_SS





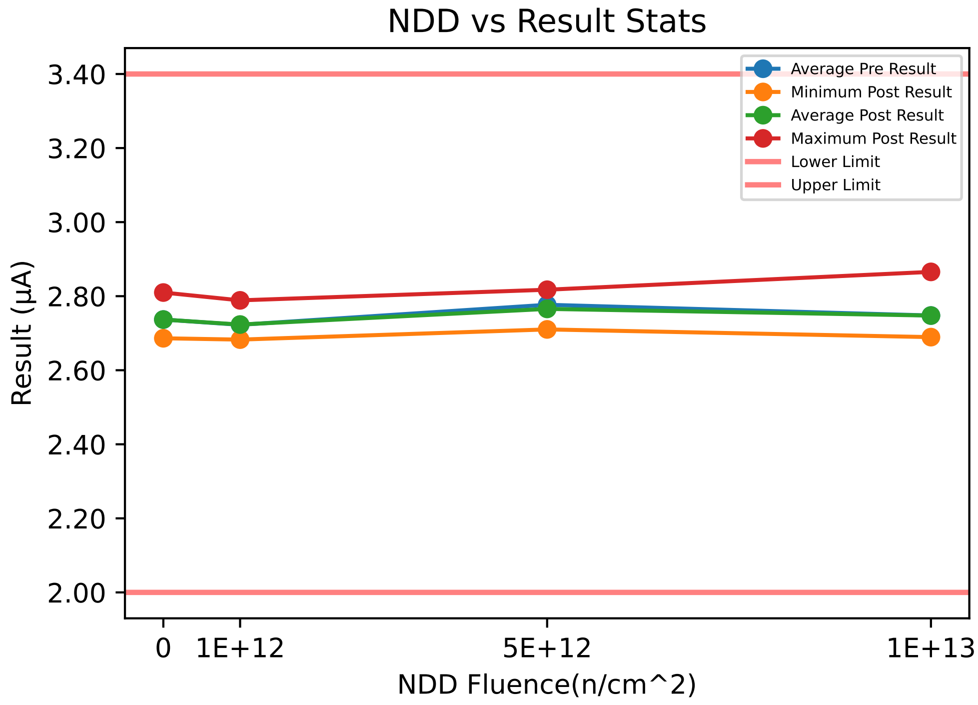
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

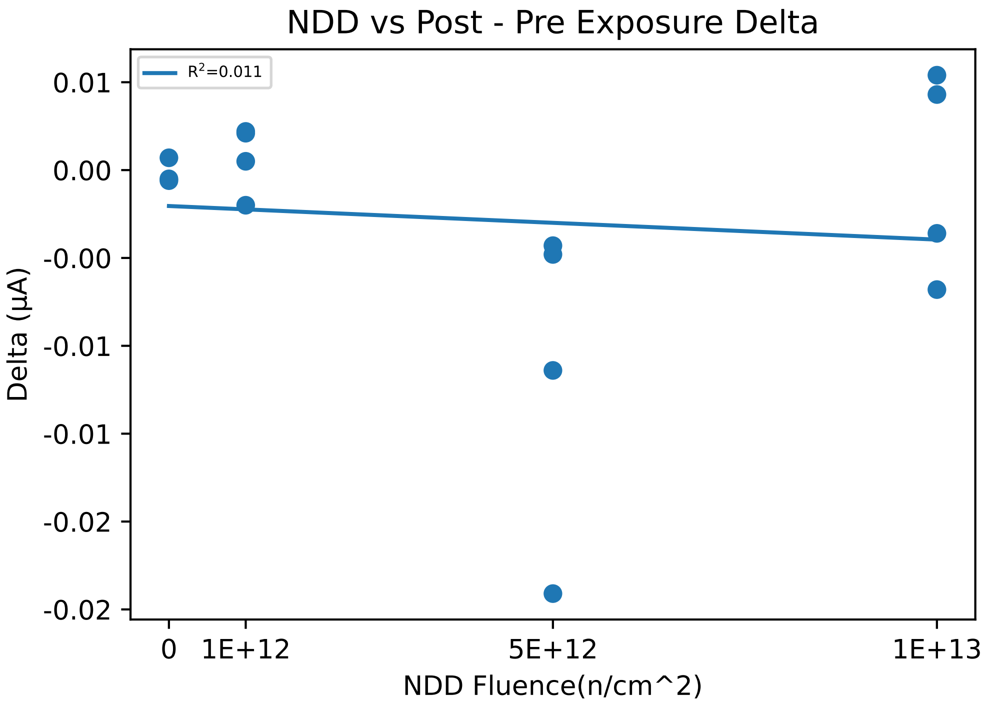
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7748	2.7723	-0.0025
2	1e+12	NDD	2.6669	2.6691	0.0022
3	1e+12	NDD	2.7172	2.72	0.0028
4	1e+12	NDD	2.6727	2.6732	0.0005
5	5e+12	NDD	2.8083	2.8042	-0.0041
6	5e+12	NDD	2.7757	2.7643	-0.0114
7	5e+12	NDD	2.7652	2.7404	-0.0248
8	5e+12	NDD	2.6996	2.6961	-0.0035
9	1e+13	NDD	2.6735	2.6767	0.0032
10	1e+13	NDD	2.6686	2.6743	0.0057
11	1e+13	NDD	2.7344	2.7278	-0.0066
12	1e+13	NDD	2.8536	2.849	-0.0046
13	0	CORRELATION	2.7	2.6988	-0.0012
14	0	CORRELATION	2.7943	2.7956	0.0013
15	0	CORRELATION	2.6731	2.6727	-0.0004

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6731	2.7225	2.7943	0.063647	2.6727	2.7224	2.7956	0.064751	-0.0012	-0.0001	0.0013	0.0012767
1e+12	2.6669	2.7079	2.7748	0.04994	2.6691	2.7087	2.7723	0.048308	-0.0025	0.00075	0.0028	0.0023756
5e+12	2.6996	2.7622	2.8083	0.04559	2.6961	2.7512	2.8042	0.045215	-0.0248	-0.01095	-0.0035	0.0099071
1e+13	2.6686	2.7325	2.8536	0.086087	2.6743	2.7319	2.849	0.081841	-0.0066	-0.000575	0.0057	0.0059478

Device Test: 18.5 CURRENT|SS_0p3V/SS/5/5/0/1000/5/100kHz//@I_SS





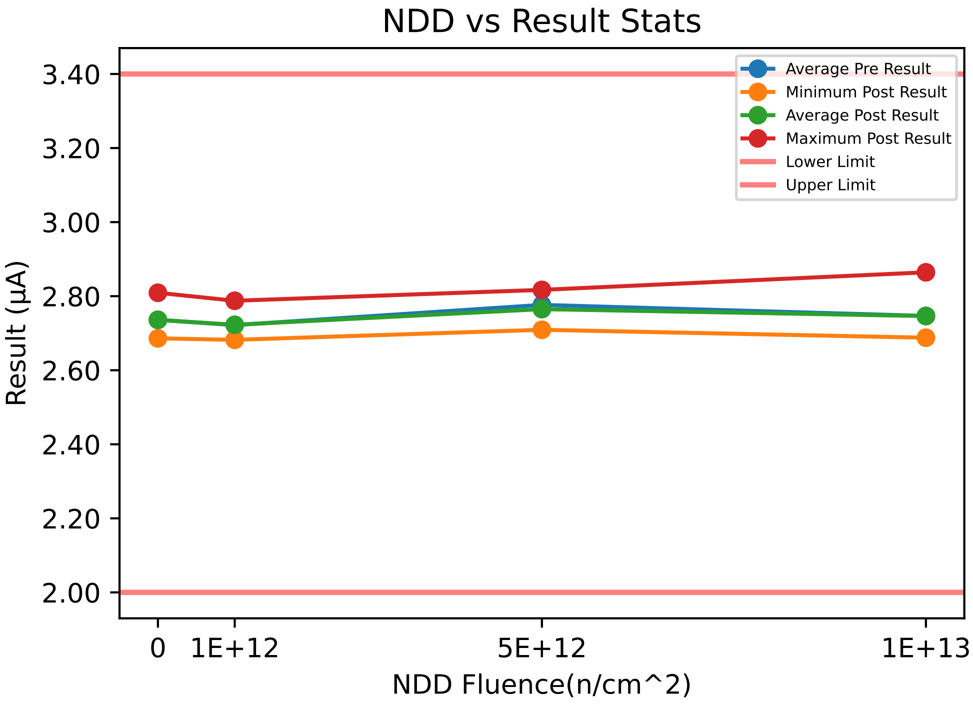
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

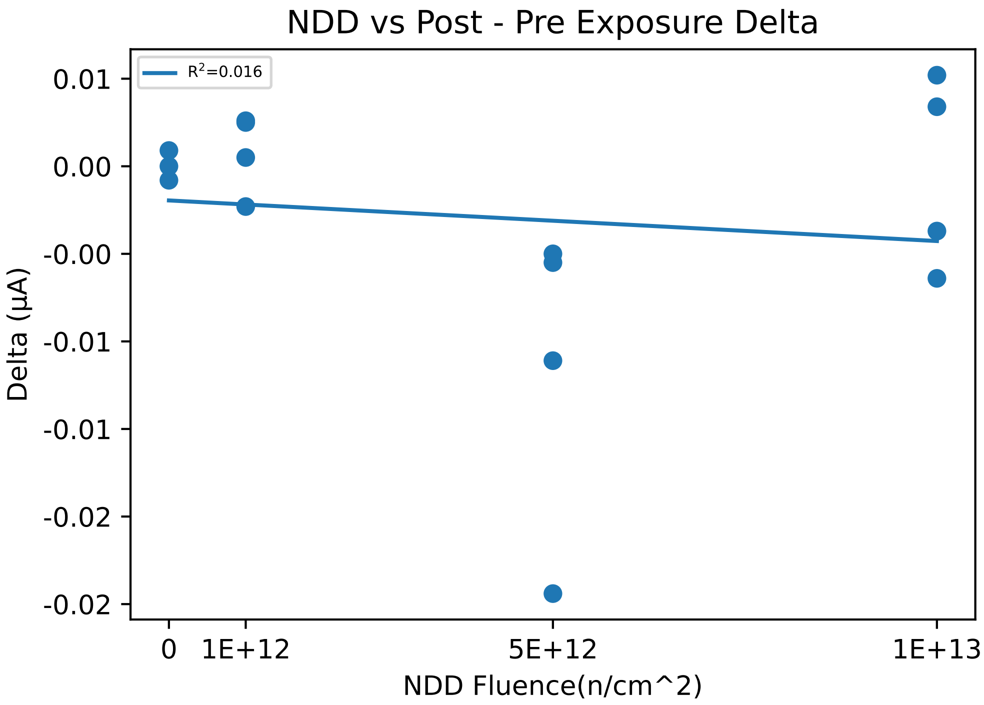
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7907	2.7887	-0.002
2	1e+12	NDD	2.6805	2.6827	0.0022
3	1e+12	NDD	2.7319	2.734	0.0021
4	1e+12	NDD	2.6876	2.6881	0.0005
5	5e+12	NDD	2.8222	2.8174	-0.0048
6	5e+12	NDD	2.7915	2.7801	-0.0114
7	5e+12	NDD	2.7789	2.7548	-0.0241
8	5e+12	NDD	2.7145	2.7102	-0.0043
9	1e+13	NDD	2.6891	2.6934	0.0043
10	1e+13	NDD	2.684	2.6894	0.0054
11	1e+13	NDD	2.7489	2.7421	-0.0068
12	1e+13	NDD	2.8692	2.8656	-0.0036
13	0	CORRELATION	2.7148	2.7143	-0.0005
14	0	CORRELATION	2.8091	2.8098	0.0007
15	0	CORRELATION	2.6869	2.6863	-0.0006

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6869	2.7369	2.8091	0.064036	2.6863	2.7368	2.8098	0.064751	-0.0006	-0.00013333	0.0007	0.00072342
1e+12	2.6805	2.7227	2.7907	0.050733	2.6827	2.7234	2.7887	0.049258	-0.002	0.0007	0.0022	0.0019613
5e+12	2.7145	2.7768	2.8222	0.045325	2.7102	2.7656	2.8174	0.045016	-0.0241	-0.01115	-0.0043	0.0092197
1e+13	2.684	2.7478	2.8692	0.08613	2.6894	2.7476	2.8656	0.082217	-0.0068	-0.000175	0.0054	0.0059645

Device Test: 18.9 CURRENT|SS_0p3V/SS/12/12/0/1000/5/100kHz//@I_SS





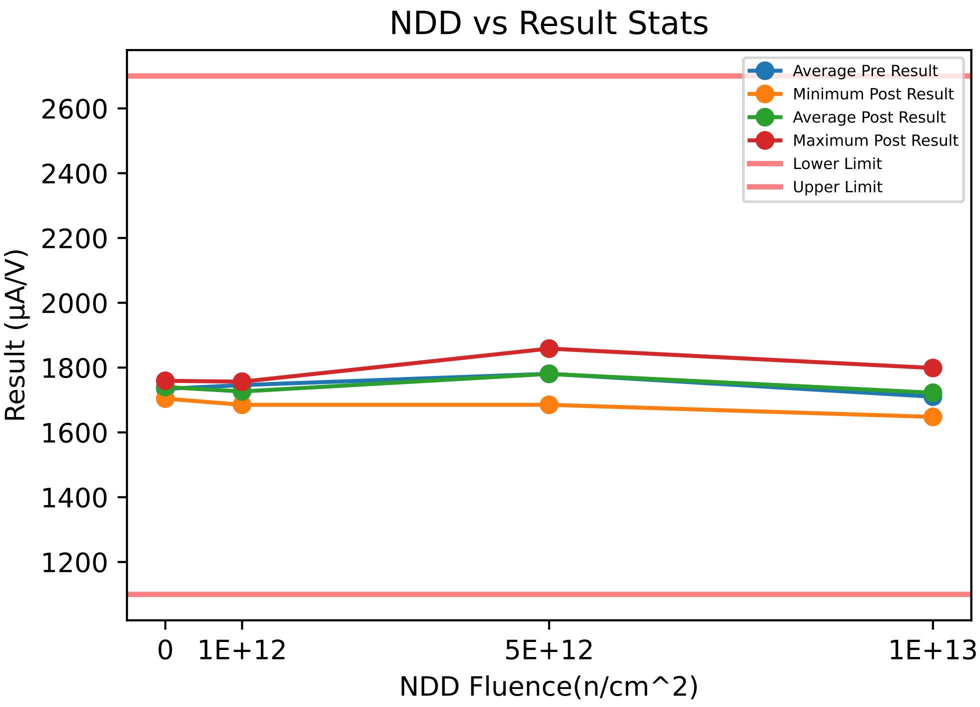
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

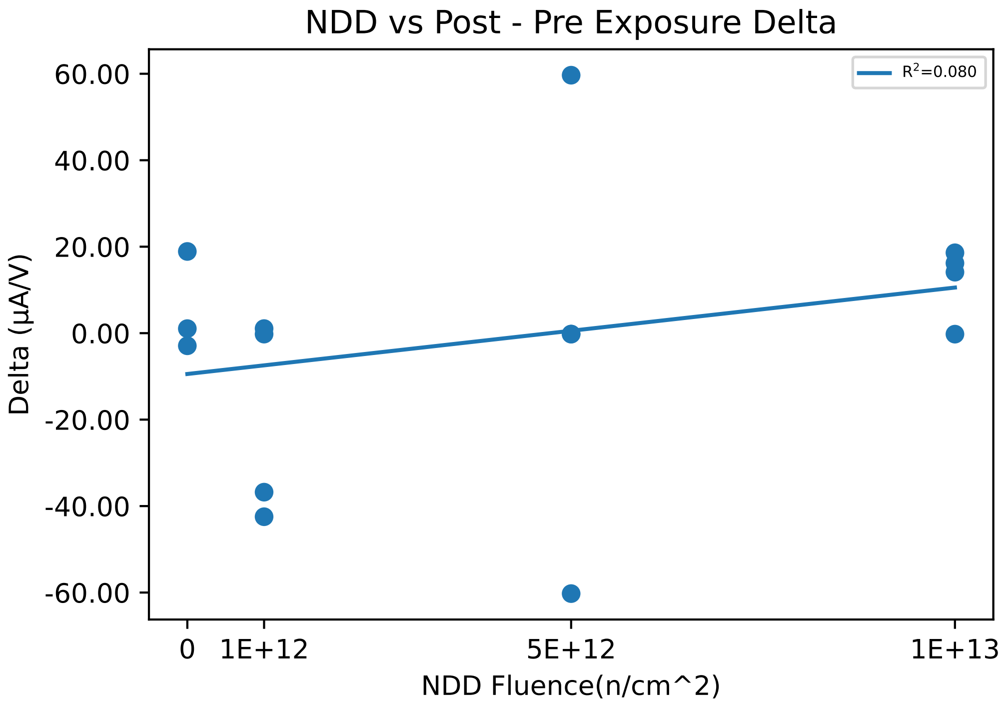
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.7899	2.7876	-0.0023
2	1e+12	NDD	2.6796	2.6821	0.0025
3	1e+12	NDD	2.7309	2.7335	0.0026
4	1e+12	NDD	2.6871	2.6876	0.0005
5	5e+12	NDD	2.8225	2.817	-0.0055
6	5e+12	NDD	2.7909	2.7798	-0.0111
7	5e+12	NDD	2.7783	2.7539	-0.0244
8	5e+12	NDD	2.7142	2.7092	-0.005
9	1e+13	NDD	2.6882	2.6916	0.0034
10	1e+13	NDD	2.6826	2.6878	0.0052
11	1e+13	NDD	2.7478	2.7414	-0.0064
12	1e+13	NDD	2.8681	2.8644	-0.0037
13	0	CORRELATION	2.7137	2.7129	-0.0008
14	0	CORRELATION	2.8083	2.8092	0.0009
15	0	CORRELATION	2.6861	2.6861	0

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6861	2.736	2.8083	0.064088	2.6861	2.7361	2.8092	0.064737	-0.0008	3.3333e-05	0.0009	0.00085049
1e+12	2.6796	2.7219	2.7899	0.05068	2.6821	2.7227	2.7876	0.04902	-0.0023	0.000825	0.0026	0.0022969
5e+12	2.7142	2.7765	2.8225	0.04549	2.7092	2.765	2.817	0.045313	-0.0244	-0.0115	-0.005	0.0090336
1e+13	2.6826	2.7467	2.8681	0.086159	2.6878	2.7463	2.8644	0.082434	-0.0064	-0.000375	0.0052	0.0055584

Device Test: 19.1 LEVEL|TRANSCONDUCTANCE//4.5/4.5/0/0/4.5/500kHz//@EA_GM





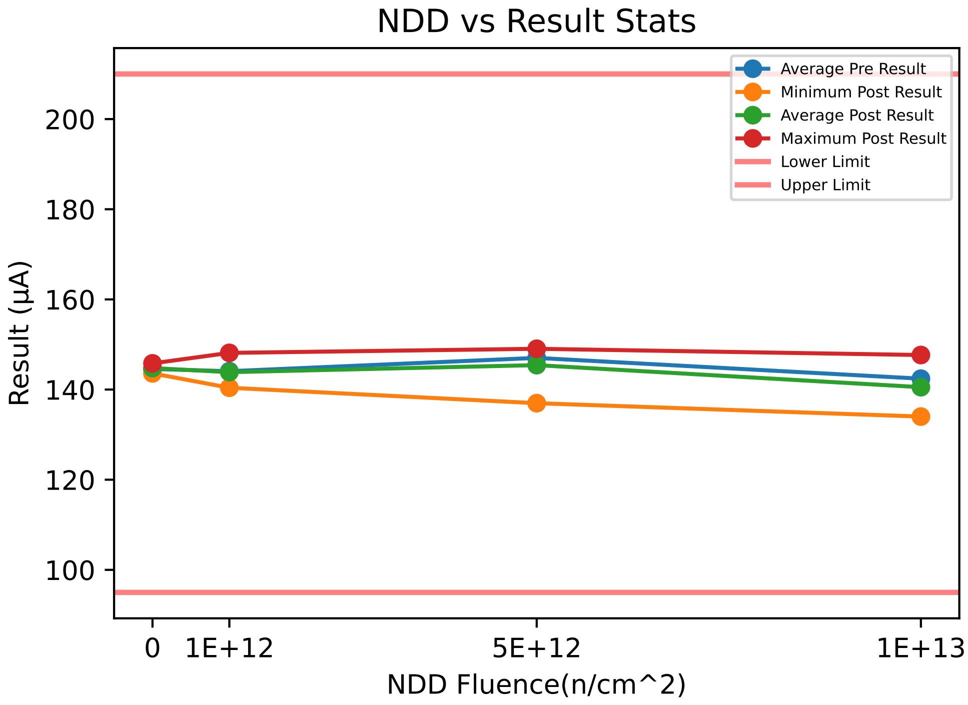
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

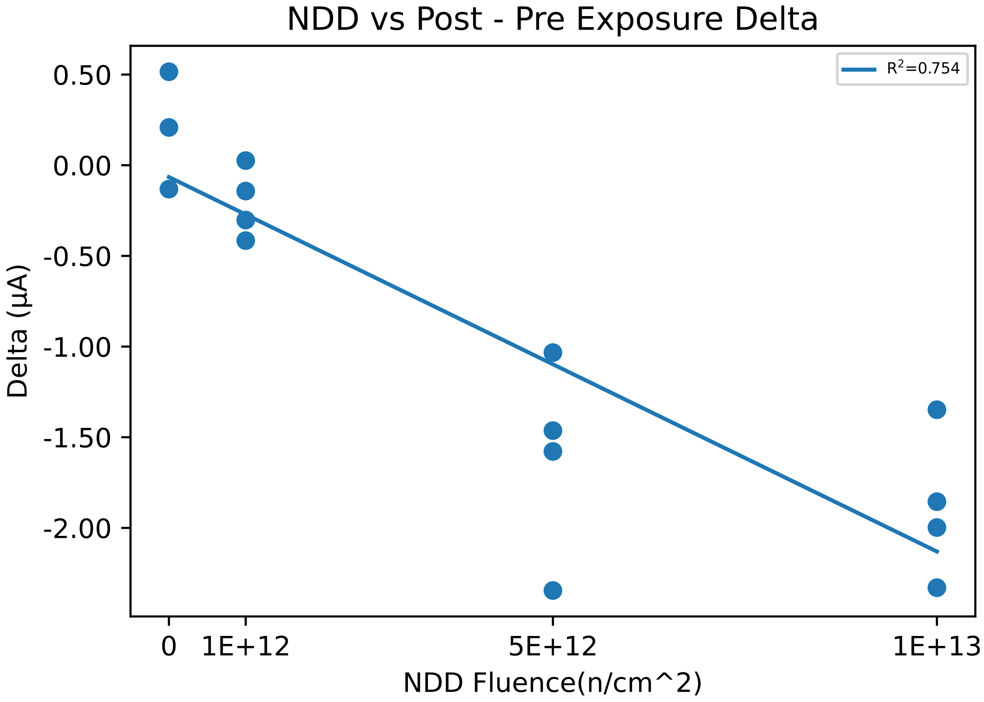
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1740.3	1741.3	1.0566
2	1e+12	NDD	1685.4	1685.2	-0.2201
3	1e+12	NDD	1799	1756.5	-42.462
4	1e+12	NDD	1759.4	1722.6	-36.779
5	5e+12	NDD	1799	1798.8	-0.2218
6	5e+12	NDD	1799	1858.6	59.669
7	5e+12	NDD	1840.3	1780	-60.244
8	5e+12	NDD	1685.4	1685.2	-0.2116
9	1e+13	NDD	1633.7	1647.9	14.105
10	1e+13	NDD	1667.7	1686.3	18.59
11	1e+13	NDD	1799	1798.8	-0.2315
12	1e+13	NDD	1740.3	1756.5	16.189
13	0	CORRELATION	1703.2	1704.3	1.0468
14	0	CORRELATION	1740.4	1759.3	18.897
15	0	CORRELATION	1759.4	1756.5	-2.9197

Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1703.2	1734.3	1759.4	28.58	1704.3	1740	1759.3	30.981	-2.9197	5.6747	18.897	11.621
1e+12	1685.4	1746	1799	47.225	1685.2	1726.4	1756.5	30.784	-42.462	-19.601	1.0566	23.239
5e+12	1685.4	1780.9	1840.3	66.583	1685.2	1780.7	1858.6	71.934	-60.244	-0.25218	59.669	48.954
1e+13	1633.7	1710.2	1799	74.033	1647.9	1722.4	1798.8	67.96	-0.2315	12.163	18.59	8.4639

Device Test: 19.10 CURRENT|EA_SOURCE//12/12/0/0/5/500kHz//@EA_I_SOURCE





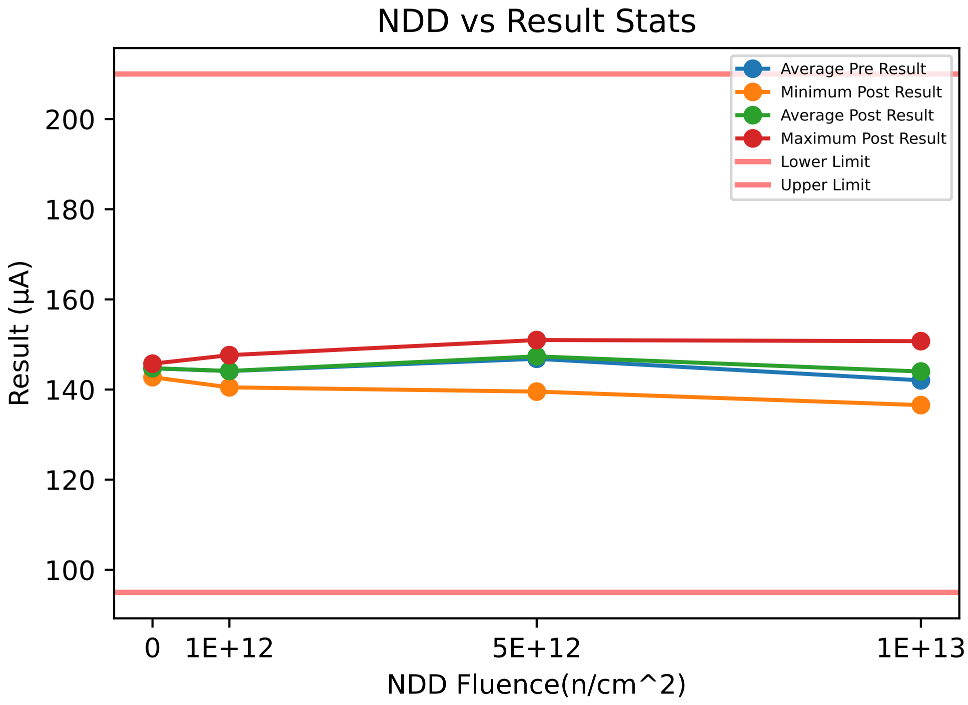
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

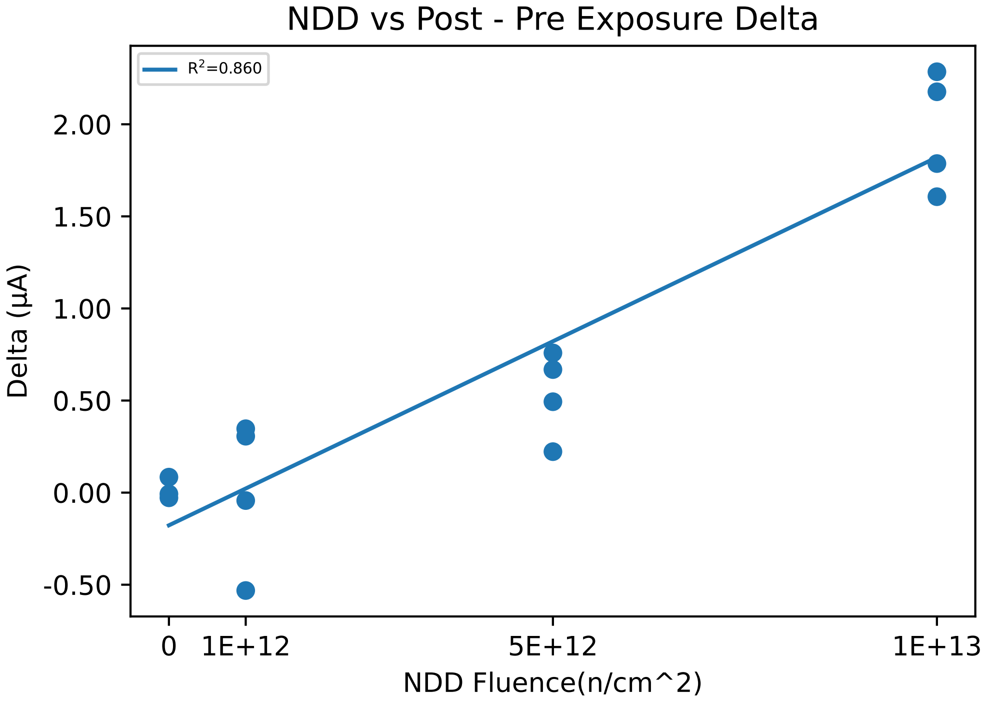
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.01	145.03	0.0257
2	1e+12	NDD	140.7	140.4	-0.3023
3	1e+12	NDD	148.55	148.14	-0.4157
4	1e+12	NDD	142	141.86	-0.1425
5	5e+12	NDD	150.51	149.04	-1.4635
6	5e+12	NDD	150.5	148.92	-1.5783
7	5e+12	NDD	147.76	146.73	-1.0332
8	5e+12	NDD	139.32	136.97	-2.3452
9	1e+13	NDD	135.86	134.01	-1.8553
10	1e+13	NDD	138.99	137.64	-1.3483
11	1e+13	NDD	149.66	147.66	-1.9979
12	1e+13	NDD	145.13	142.8	-2.3298
13	0	CORRELATION	143.38	143.59	0.2084
14	0	CORRELATION	145.29	145.81	0.5155
15	0	CORRELATION	145.03	144.9	-0.1317

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.38	144.57	145.29	1.0373	143.59	144.76	145.81	1.1155	-0.1317	0.1974	0.5155	0.32374
1e+12	140.7	144.07	148.55	3.4921	140.4	143.86	148.14	3.4465	-0.4157	-0.2087	0.0257	0.1923
5e+12	139.32	147.02	150.51	5.2946	136.97	145.42	149.04	5.7276	-2.3452	-1.605	-1.0332	0.54638
1e+13	135.86	142.41	149.66	6.1774	134.01	140.53	147.66	5.9686	-2.3298	-1.8828	-1.3483	0.40805

Device Test: 19.11 CURRENT|EA_SINK//12/12/0/0/5/500kHz//@EA_I_SINK





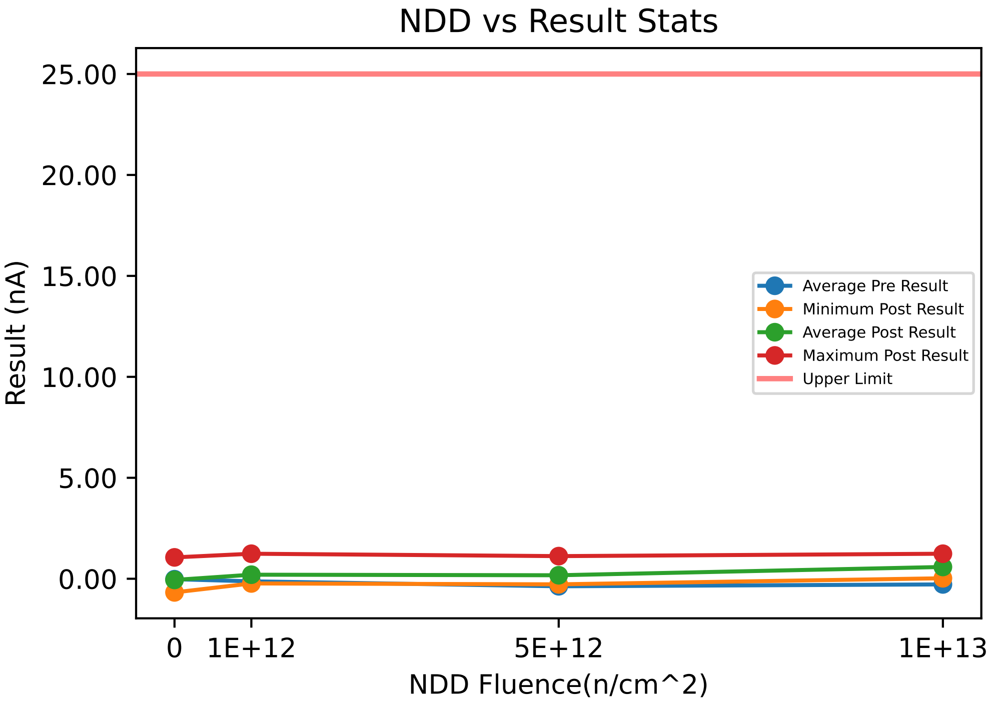
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

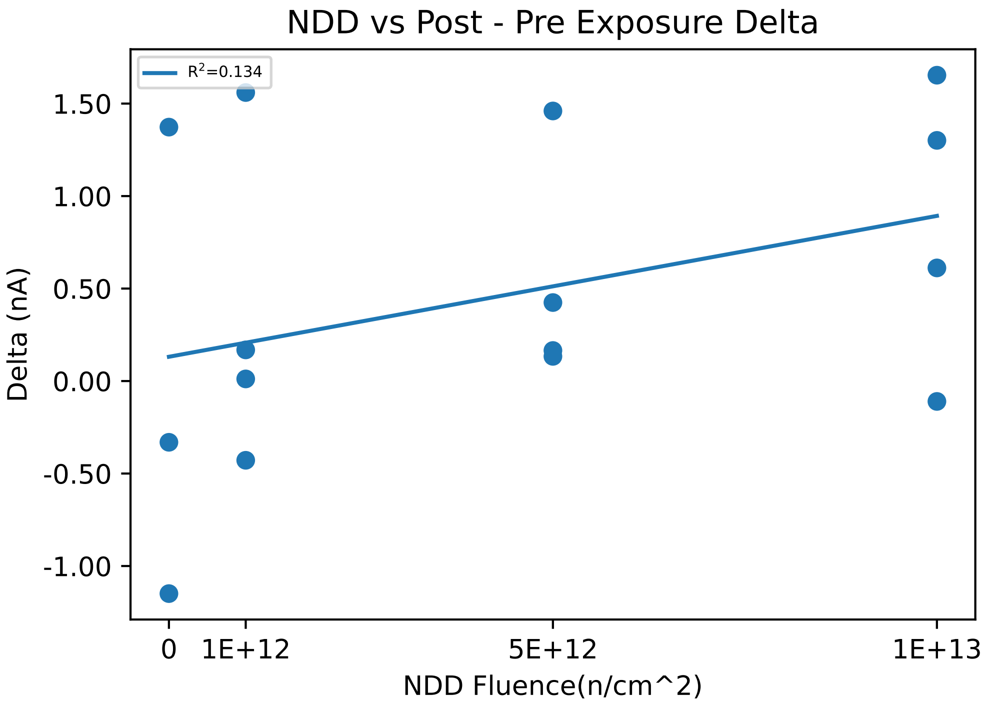
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.75	146.1	0.3469
2	1e+12	NDD	141.02	140.49	-0.5315
3	1e+12	NDD	147.33	147.63	0.3063
4	1e+12	NDD	142.31	142.26	-0.043
5	5e+12	NDD	150.23	150.98	0.7585
6	5e+12	NDD	150.12	150.62	0.4936
7	5e+12	NDD	147.63	148.3	0.6682
8	5e+12	NDD	139.32	139.54	0.2225
9	1e+13	NDD	134.76	136.55	1.7867
10	1e+13	NDD	138.83	141.01	2.1765
11	1e+13	NDD	149.13	150.73	1.6068
12	1e+13	NDD	145.44	147.73	2.2852
13	0	CORRELATION	142.65	142.73	0.0841
14	0	CORRELATION	145.76	145.74	-0.028
15	0	CORRELATION	145.72	145.72	-0.0072

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	142.65	144.71	145.76	1.7862	142.73	144.73	145.74	1.7274	-0.028	0.0163	0.0841	0.05963
1e+12	141.02	144.1	147.33	2.9354	140.49	144.12	147.63	3.3115	-0.5315	0.019675	0.3469	0.407
5e+12	139.32	146.83	150.23	5.1438	139.54	147.36	150.98	5.3446	0.2225	0.5357	0.7585	0.23598
1e+13	134.76	142.04	149.13	6.4567	136.55	144	150.73	6.4217	1.6068	1.9638	2.2852	0.32008

Device Test: 19.12 CURRENT|EA//12/12/0/0/5/500kHz//@EA_IB


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

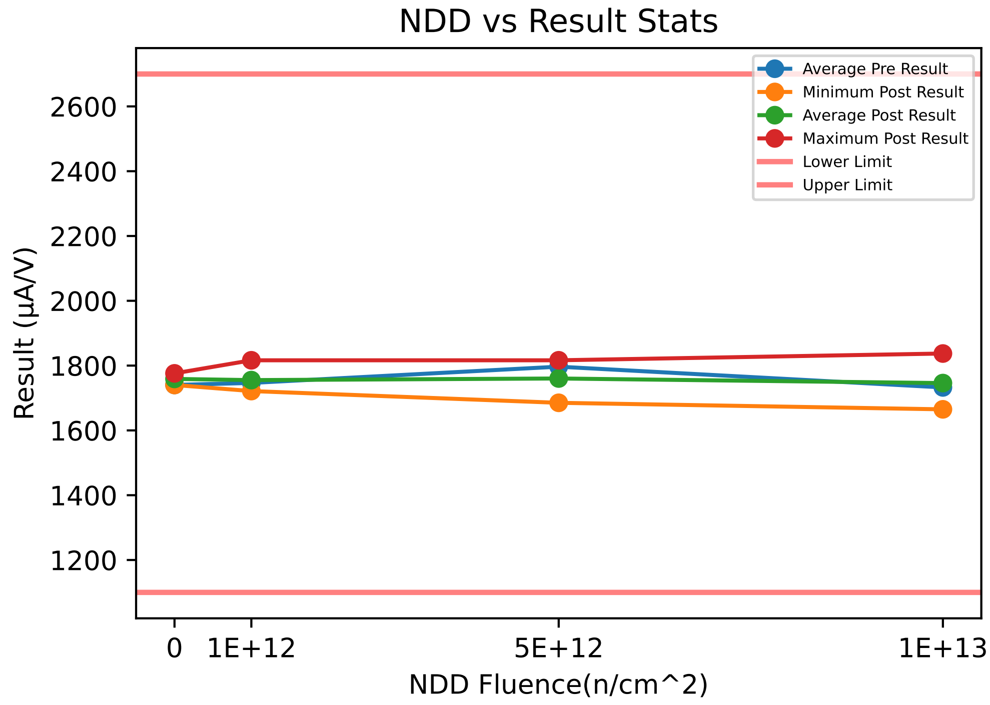
Test Results (Upper Limit = 25.0 (nA))

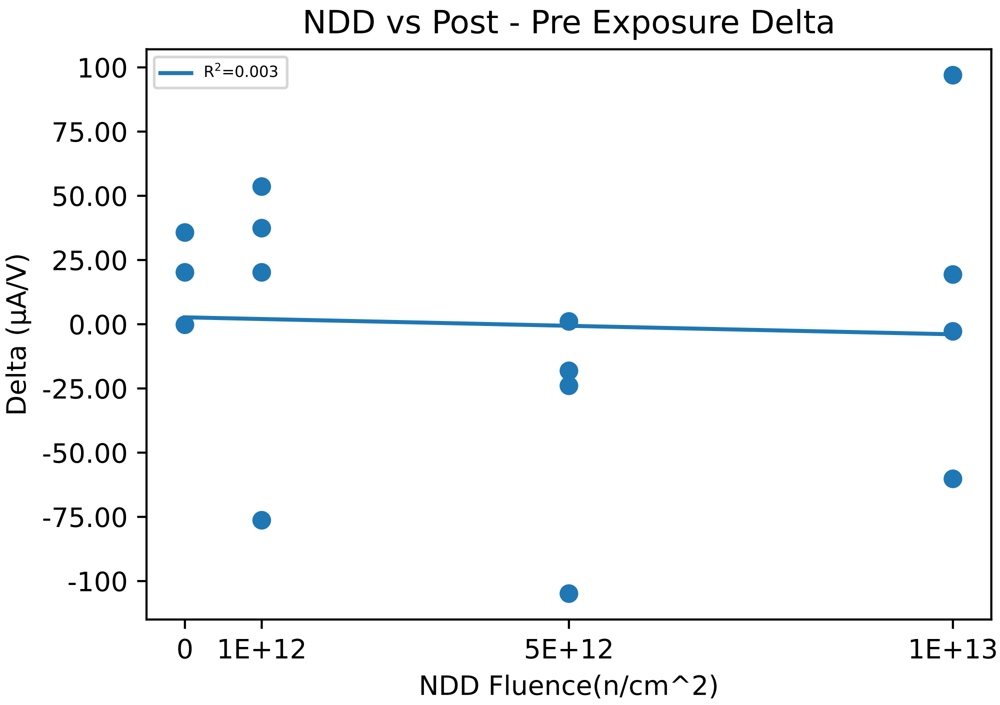
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2002	-0.2282	-0.4284
2	1e+12	NDD	-0.401	-0.2326	0.1684
3	1e+12	NDD	-0.3206	1.2392	1.5598
4	1e+12	NDD	0.0129	0.0244	0.0115
5	5e+12	NDD	-0.4197	0.0047	0.4244
6	5e+12	NDD	-0.3394	1.1207	1.4601
7	5e+12	NDD	-0.2899	-0.1565	0.1334
8	5e+12	NDD	-0.4415	-0.2763	0.1652
9	1e+13	NDD	-0.3519	0.9492	1.3011
10	1e+13	NDD	0.1346	0.0244	-0.1102
11	1e+13	NDD	-0.4883	0.1233	0.6116
12	1e+13	NDD	-0.4143	1.2392	1.6535
13	0	CORRELATION	0.5904	-0.5587	-1.1491
14	0	CORRELATION	-0.3448	-0.6759	-0.3311
15	0	CORRELATION	-0.3144	1.0584	1.3728

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3448	-0.022933	0.5904	0.53138	-0.6759	-0.058733	1.0584	0.96924	-1.1491	-0.0358	1.3728	1.2866
1e+12	-0.401	-0.12713	0.2002	0.28236	-0.2326	0.2007	1.2392	0.70268	-0.4284	0.32783	1.5598	0.85929
5e+12	-0.4415	-0.37262	-0.2899	0.070491	-0.2763	0.17315	1.1207	0.64211	0.1334	0.54578	1.4601	0.62333
1e+13	-0.4883	-0.27997	0.1346	0.28195	0.0244	0.58403	1.2392	0.60223	-0.1102	0.864	1.6535	0.78041

Device Test: 19.13 LEVEL|TRANSCONDUCTANCE//14/14/0/0/5/500kHz//@EA_GM


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

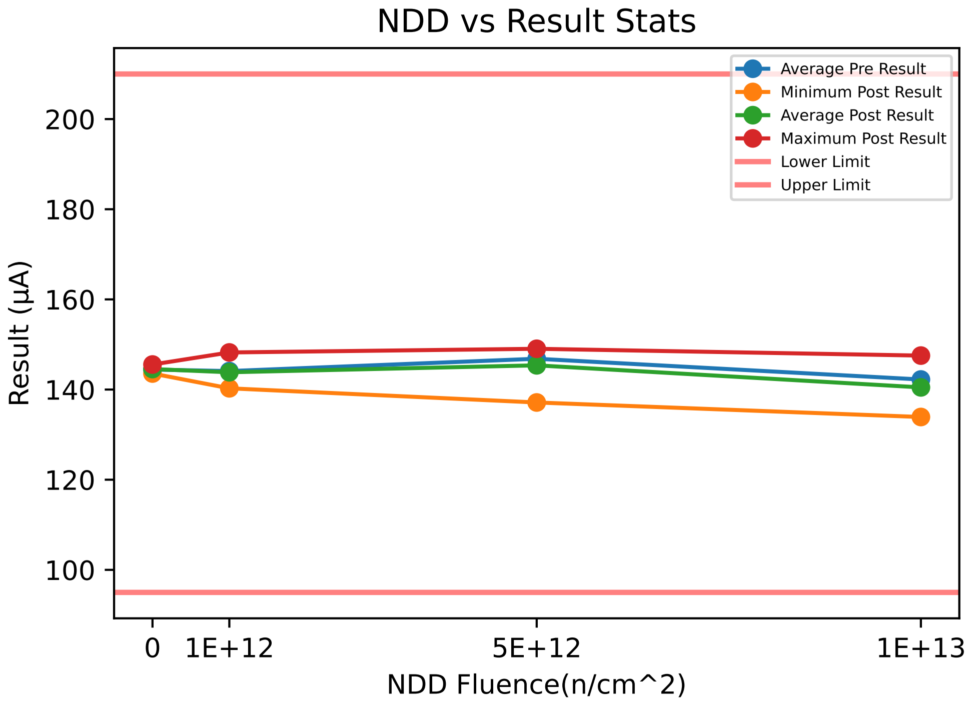
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

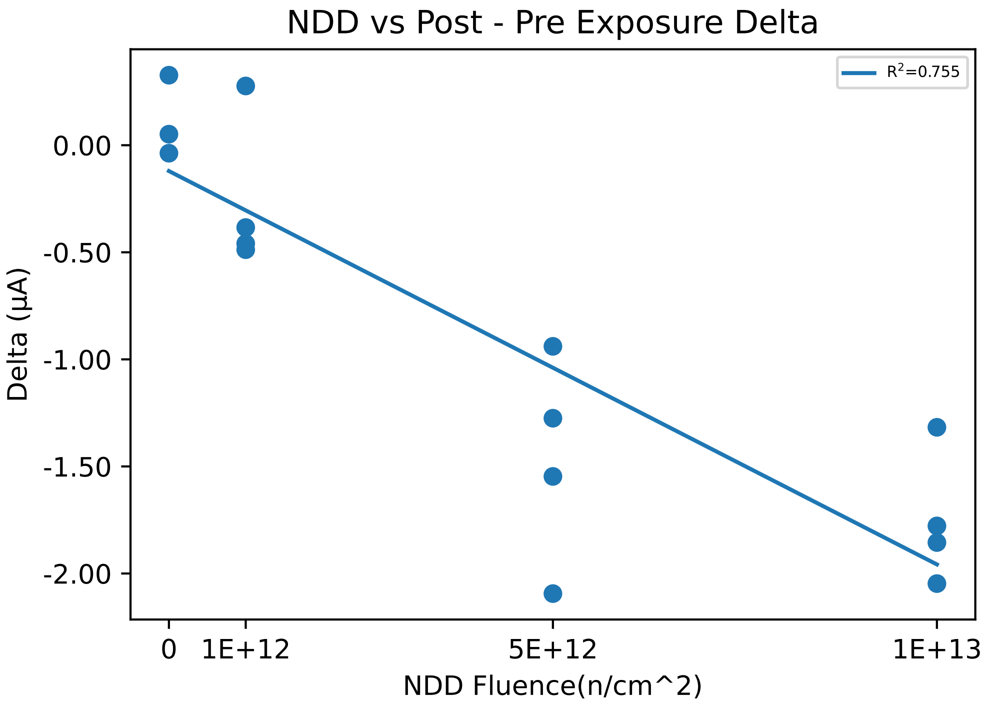
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1798.9	1722.6	-76.32
2	1e+12	NDD	1667.8	1721.4	53.597
3	1e+12	NDD	1779	1816.4	37.403
4	1e+12	NDD	1740.3	1760.5	20.197
5	5e+12	NDD	1883.7	1778.8	-104.87
6	5e+12	NDD	1840.3	1816.4	-23.949
7	5e+12	NDD	1759.4	1760.5	1.0892
8	5e+12	NDD	1703.3	1685.2	-18.144
9	1e+13	NDD	1667.8	1665	-2.7724
10	1e+13	NDD	1703.2	1722.6	19.359
11	1e+13	NDD	1819.4	1759.3	-60.193
12	1e+13	NDD	1740.3	1837.3	96.957
13	0	CORRELATION	1740.3	1760.5	20.197
14	0	CORRELATION	1740.3	1740.1	-0.2076
15	0	CORRELATION	1740.3	1776	35.712

Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1740.3	1740.3	1740.3	0.0361	1740.1	1758.9	1776	17.995	-0.2076	18.567	35.712	18.015
1e+12	1667.8	1746.5	1798.9	57.824	1721.4	1755.2	1816.4	44.625	-76.32	8.7192	53.597	58.31
5e+12	1703.3	1796.7	1883.7	80.788	1685.2	1760.2	1816.4	55.169	-104.87	-36.469	1.0892	46.84
1e+13	1667.8	1732.7	1819.4	64.969	1665	1746	1837.3	72.13	-60.193	13.338	96.957	65.051

Device Test: 19.14 CURRENT|EA_SOURCE//14/14/0/0/5/500kHz//@EA_I_SOURCE





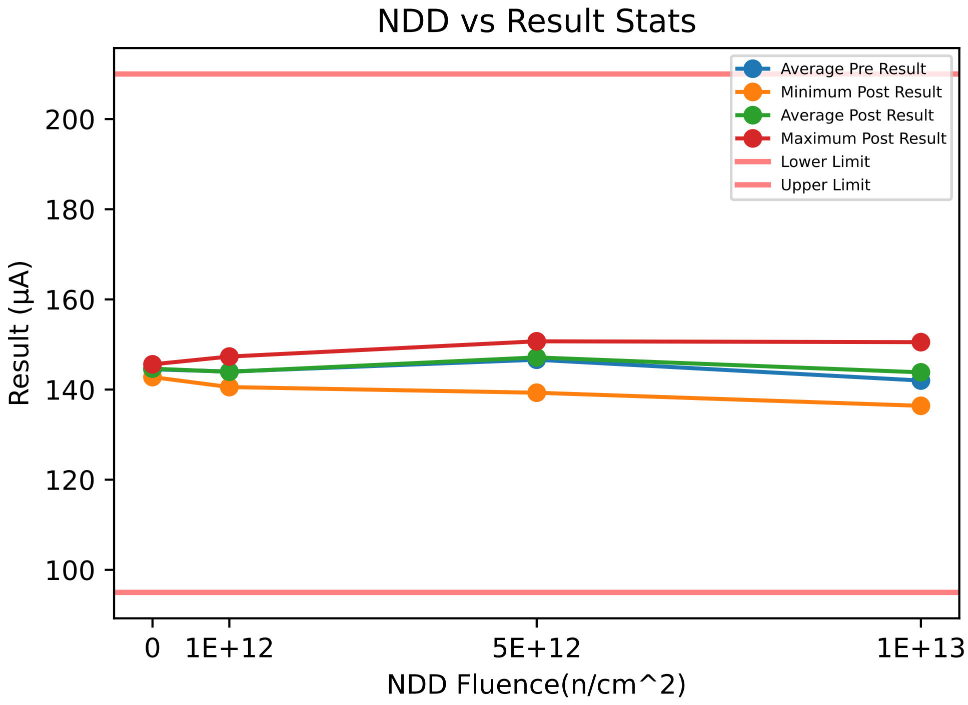
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

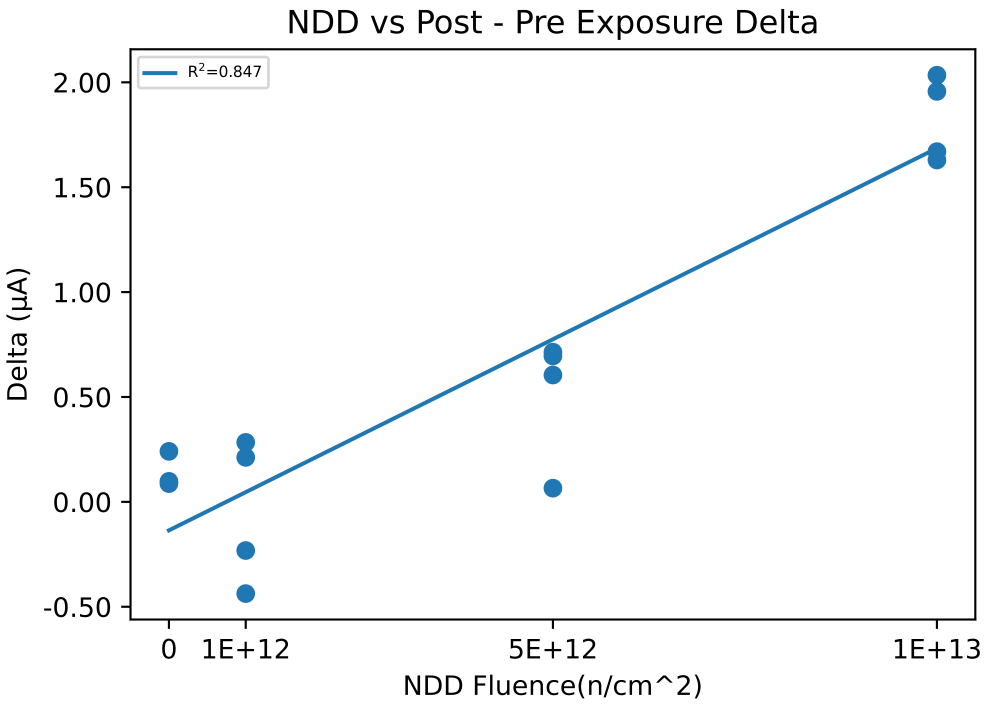
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	144.88	145.16	0.2767
2	1e+12	NDD	140.73	140.27	-0.4594
3	1e+12	NDD	148.61	148.23	-0.3843
4	1e+12	NDD	142.16	141.67	-0.4878
5	5e+12	NDD	150.32	149.04	-1.2749
6	5e+12	NDD	150.12	148.58	-1.5467
7	5e+12	NDD	147.67	146.73	-0.9392
8	5e+12	NDD	139.23	137.13	-2.0939
9	1e+13	NDD	135.77	133.91	-1.8554
10	1e+13	NDD	138.87	137.55	-1.3173
11	1e+13	NDD	149.31	147.53	-1.7779
12	1e+13	NDD	144.97	142.92	-2.0472
13	0	CORRELATION	143.5	143.56	0.0516
14	0	CORRELATION	145.23	145.55	0.327
15	0	CORRELATION	144.56	144.52	-0.0373

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.5	144.43	145.23	0.86901	143.56	144.54	145.55	0.99945	-0.0373	0.11377	0.327	0.18994
1e+12	140.73	144.1	148.61	3.4686	140.27	143.83	148.23	3.5793	-0.4878	-0.2637	0.2767	0.3629
5e+12	139.23	146.83	150.32	5.2131	137.13	145.37	149.04	5.5821	-2.0939	-1.4637	-0.9392	0.48812
1e+13	135.77	142.23	149.31	6.0758	133.91	140.48	147.53	5.9851	-2.0472	-1.7495	-1.3173	0.30954

Device Test: 19.15 CURRENT|EA_SINK//14/14/0/0/5/500kHz//@EA_I_SINK





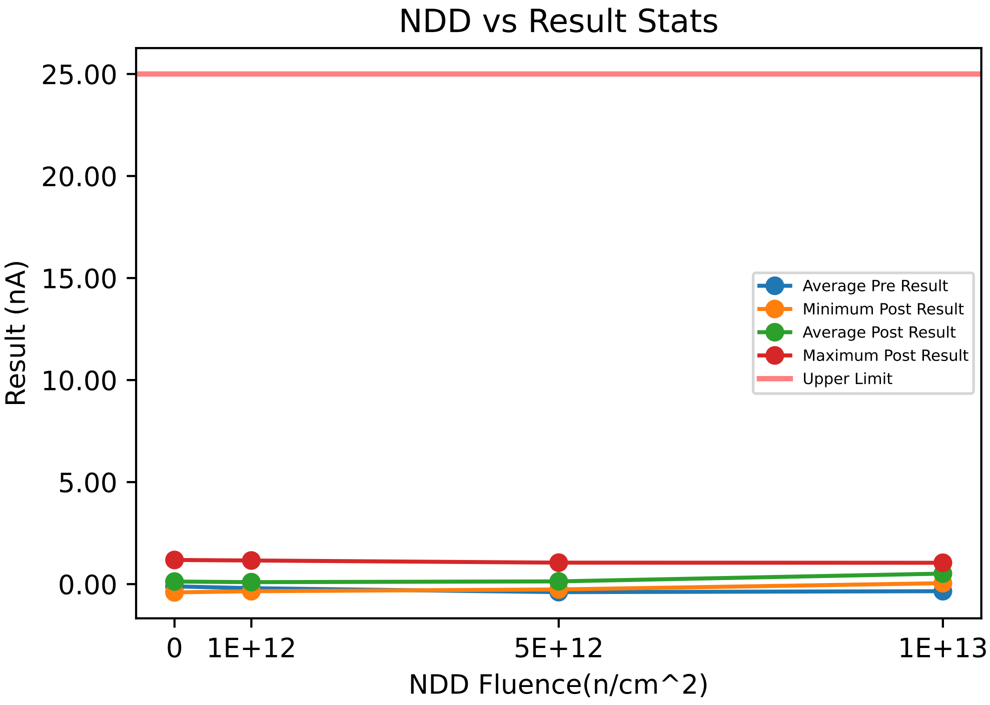
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

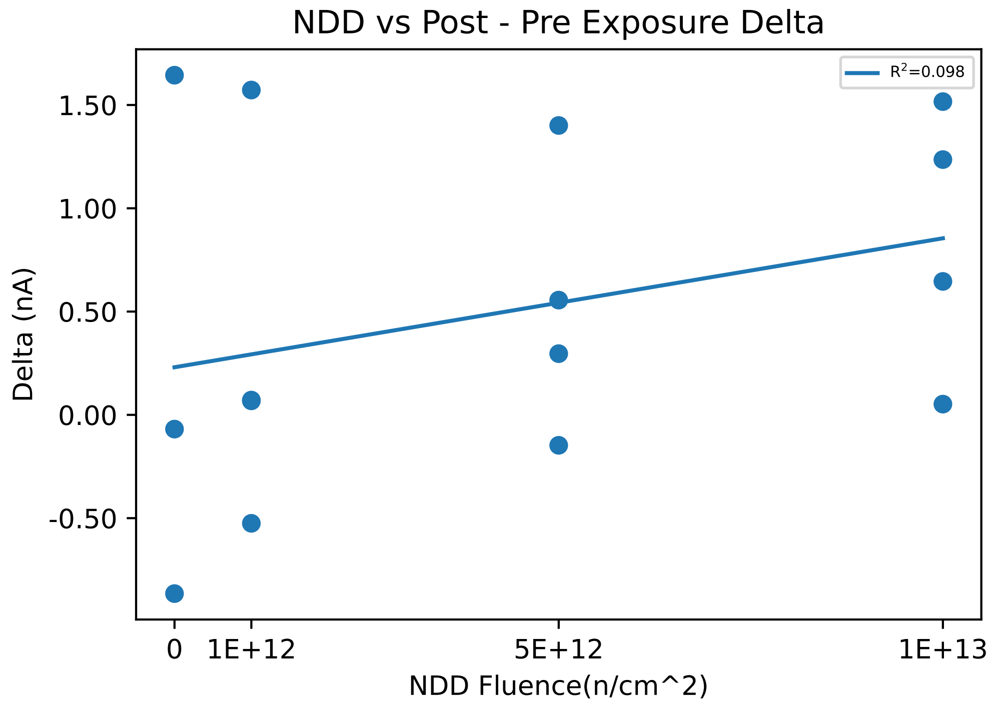
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.63	145.91	0.2836
2	1e+12	NDD	140.99	140.55	-0.4373
3	1e+12	NDD	147.11	147.32	0.2121
4	1e+12	NDD	142.21	141.98	-0.232
5	5e+12	NDD	150.01	150.7	0.6956
6	5e+12	NDD	149.75	150.46	0.7136
7	5e+12	NDD	147.47	148.08	0.6047
8	5e+12	NDD	139.23	139.29	0.0653
9	1e+13	NDD	134.76	136.39	1.6297
10	1e+13	NDD	138.92	140.88	1.9567
11	1e+13	NDD	148.84	150.51	1.6696
12	1e+13	NDD	145.44	147.48	2.034
13	0	CORRELATION	142.52	142.77	0.2408
14	0	CORRELATION	145.45	145.55	0.0978
15	0	CORRELATION	145.5	145.59	0.0871

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	142.52	144.49	145.5	1.7045	142.77	144.63	145.59	1.6188	0.0871	0.1419	0.2408	0.085817
1e+12	140.99	143.98	147.11	2.8617	140.55	143.94	147.32	3.1952	-0.4373	-0.0434	0.2836	0.34782
5e+12	139.23	146.61	150.01	5.0531	139.29	147.13	150.7	5.3587	0.0653	0.5198	0.7136	0.30673
1e+13	134.76	141.99	148.84	6.3387	136.39	143.81	150.51	6.3767	1.6297	1.8225	2.034	0.20272

Device Test: 19.16 CURRENT|EA//14/14/0/0/5/500kHz//@EA_IB


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

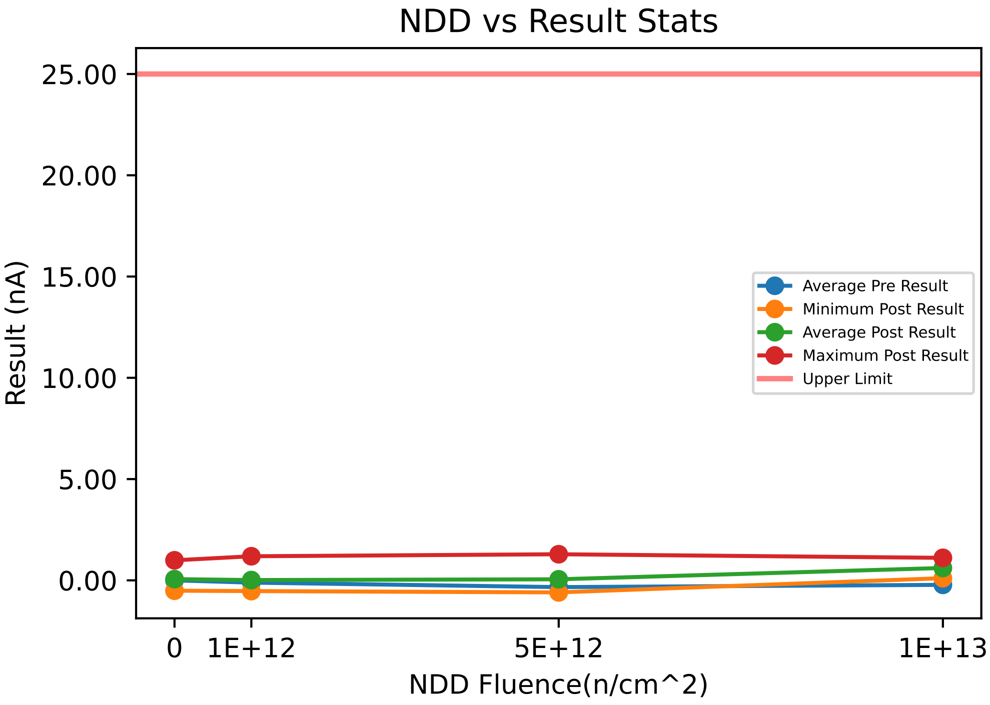
Test Results (Upper Limit = 25.0 (nA))

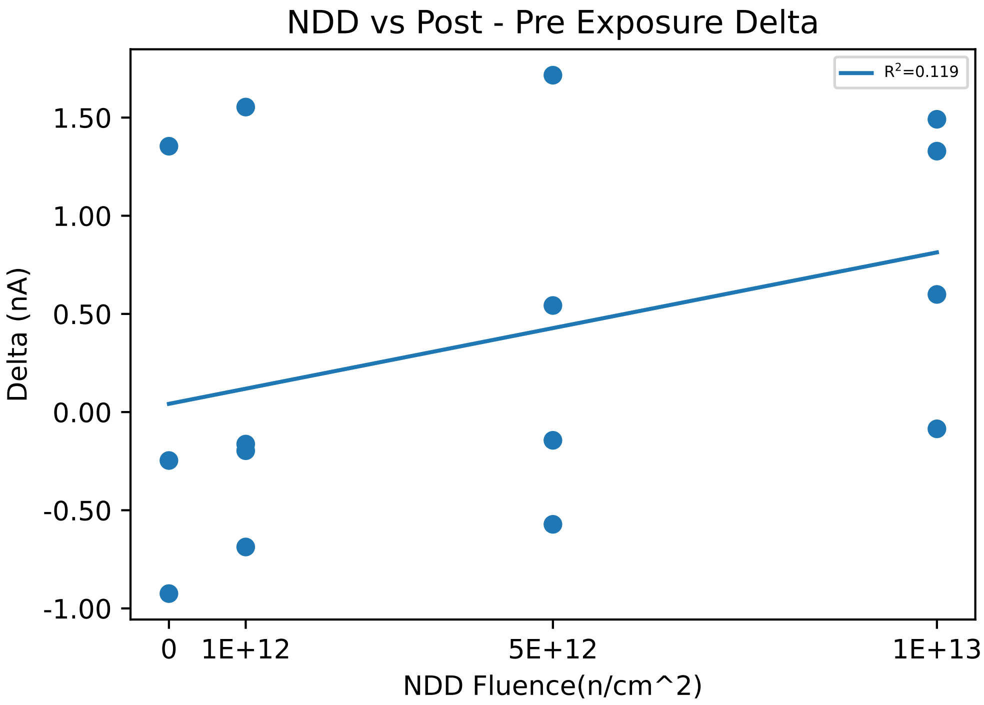
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2064	-0.3186	-0.525
2	1e+12	NDD	-0.4197	-0.3481	0.0716
3	1e+12	NDD	-0.4143	1.1581	1.5724
4	1e+12	NDD	-0.1713	-0.1035	0.0678
5	5e+12	NDD	-0.582	-0.0265	0.5555
6	5e+12	NDD	-0.3487	1.0521	1.4008
7	5e+12	NDD	-0.0839	-0.2313	-0.1474
8	5e+12	NDD	-0.557	-0.2607	0.2963
9	1e+13	NDD	-0.3956	0.8401	1.2357
10	1e+13	NDD	0.0784	0.1304	0.052
11	1e+13	NDD	-0.6007	0.0453	0.646
12	1e+13	NDD	-0.4705	1.0459	1.5164
13	0	CORRELATION	0.4593	-0.4059	-0.8652
14	0	CORRELATION	-0.3323	-0.4012	-0.0689
15	0	CORRELATION	-0.4611	1.1831	1.6442

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4611	-0.11137	0.4593	0.49839	-0.4059	0.12533	1.1831	0.91606	-0.8652	0.2367	1.6442	1.2823
1e+12	-0.4197	-0.19973	0.2064	0.29449	-0.3481	0.096975	1.1581	0.71577	-0.525	0.2967	1.5724	0.89548
5e+12	-0.582	-0.3929	-0.0839	0.23103	-0.2607	0.1334	1.0521	0.62126	-0.1474	0.5263	1.4008	0.65125
1e+13	-0.6007	-0.3471	0.0784	0.29605	0.0453	0.51543	1.0459	0.50202	0.052	0.86252	1.5164	0.65081

Device Test: 19.17 CURRENT|EA//4.5/4.5/0/0/4.5/100kHz//@EA_IB





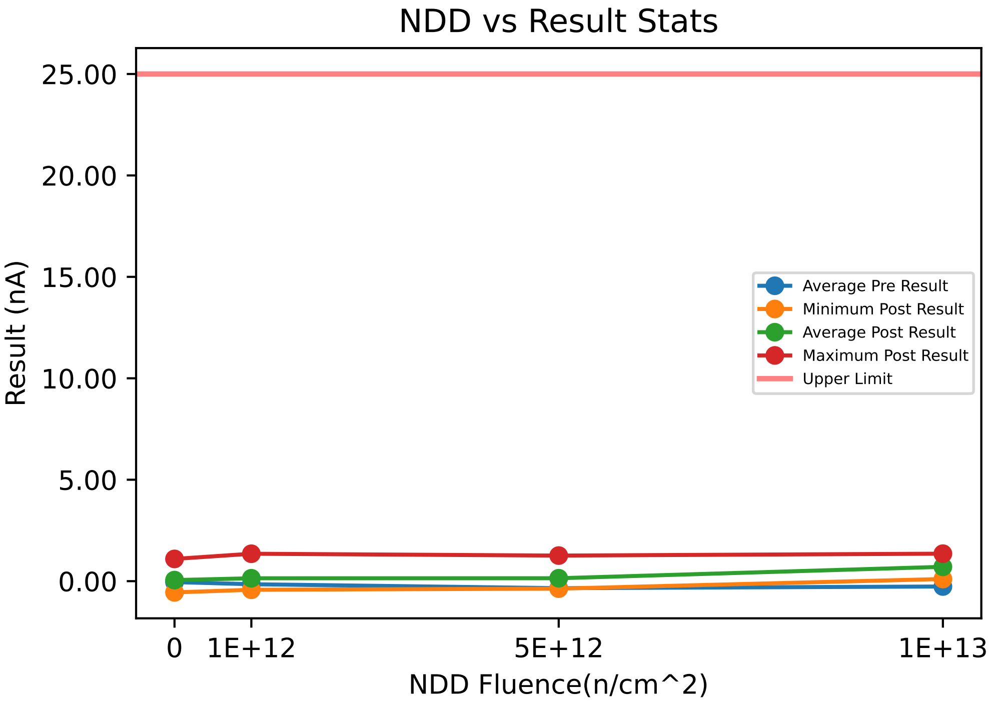
Test Results (Upper Limit = 25.0 (nA))

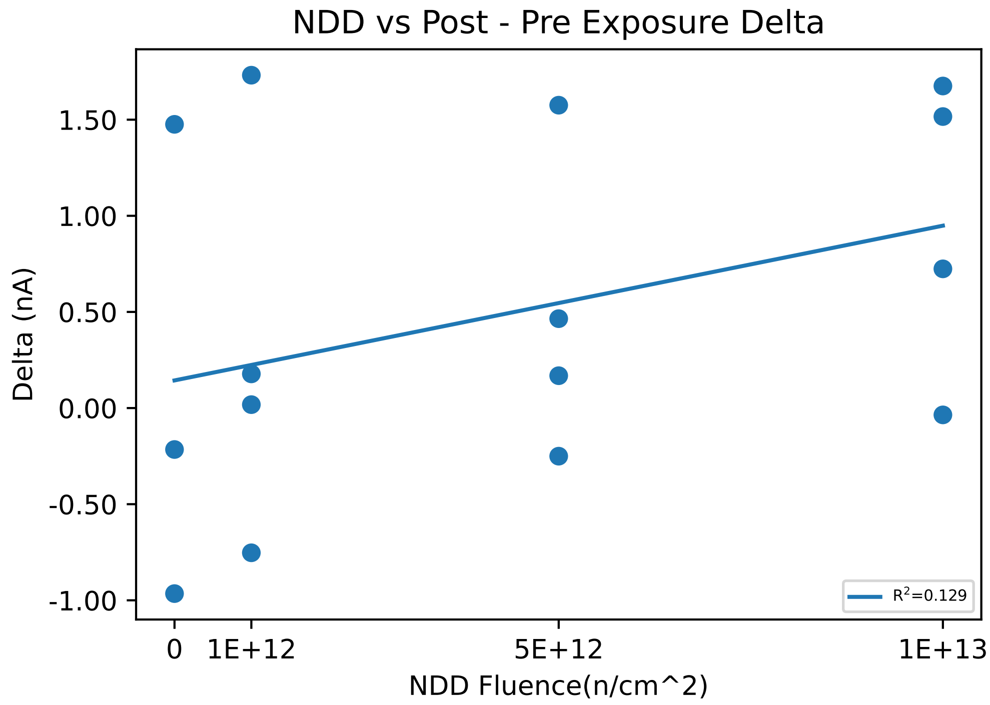
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.2314	-0.4558	-0.6872
2	1e+12	NDD	-0.3323	-0.5292	-0.1969
3	1e+12	NDD	-0.3643	1.1893	1.5536
4	1e+12	NDD	0.016	-0.1471	-0.1631
5	5e+12	NDD	-0.5601	-0.0172	0.5429
6	5e+12	NDD	-0.4268	1.2891	1.7159
7	5e+12	NDD	0.1034	-0.4683	-0.5717
8	5e+12	NDD	-0.4509	-0.5947	-0.1438
9	1e+13	NDD	-0.2801	1.049	1.3291
10	1e+13	NDD	0.2626	0.1772	-0.0854
11	1e+13	NDD	-0.4915	0.1077	0.5992
12	1e+13	NDD	-0.38	1.1114	1.4914
13	0	CORRELATION	0.6278	-0.2968	-0.9246
14	0	CORRELATION	-0.2637	-0.5104	-0.2467
15	0	CORRELATION	-0.3643	0.9898	1.3541

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3643	-6.6667e-05	0.6278	0.54607	-0.5104	0.060867	0.9898	0.81154	-0.9246	0.060933	1.3541	1.1701
1e+12	-0.3643	-0.1123	0.2314	0.28664	-0.5292	0.0143	1.1893	0.80064	-0.6872	0.1266	1.5536	0.98102
5e+12	-0.5601	-0.3336	0.1034	0.29705	-0.5947	0.052225	1.2891	0.86103	-0.5717	0.38582	1.7159	0.99852
1e+13	-0.4915	-0.22225	0.2626	0.33457	0.1077	0.61132	1.1114	0.54275	-0.0854	0.83357	1.4914	0.7252

Device Test: 19.18 CURRENT|EA//4.5/4.5/0/0/4.5/1MHz//@EA_IB





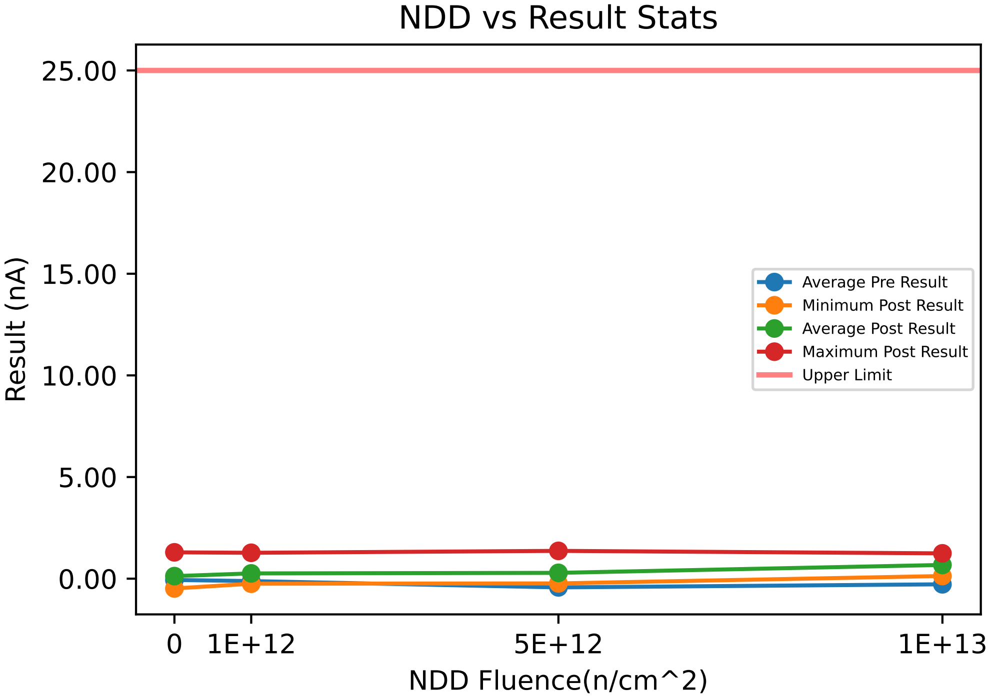
Test Results (Upper Limit = 25.0 (nA))

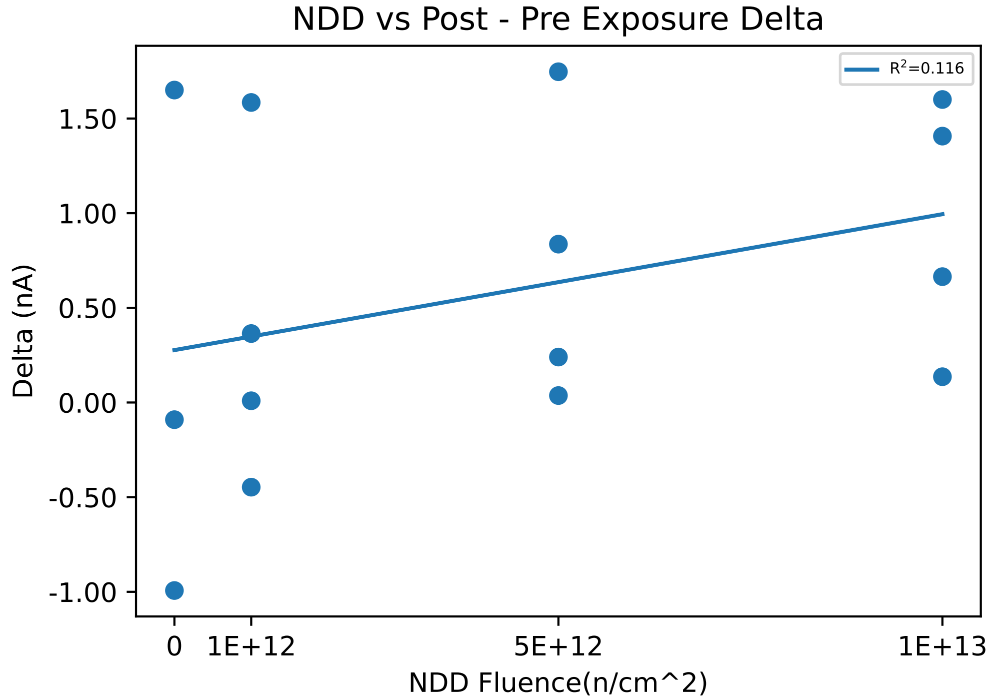
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3282	-0.4246	-0.7528
2	1e+12	NDD	-0.4291	-0.2513	0.1778
3	1e+12	NDD	-0.38	1.3514	1.7314
4	1e+12	NDD	-0.1244	-0.1066	0.0178
5	5e+12	NDD	-0.4353	0.0297	0.465
6	5e+12	NDD	-0.3144	1.261	1.5754
7	5e+12	NDD	-0.1182	-0.3685	-0.2503
8	5e+12	NDD	-0.5164	-0.3481	0.1683
9	1e+13	NDD	-0.3206	1.3546	1.6752
10	1e+13	NDD	0.1409	0.1054	-0.0355
11	1e+13	NDD	-0.5071	0.217	0.7241
12	1e+13	NDD	-0.3675	1.1488	1.5163
13	0	CORRELATION	0.581	-0.3841	-0.9651
14	0	CORRELATION	-0.3386	-0.5542	-0.2156
15	0	CORRELATION	-0.38	1.0958	1.4758

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.38	-0.045867	0.581	0.54328	-0.5542	0.0525	1.0958	0.90752	-0.9651	0.098367	1.4758	1.2504
1e+12	-0.4291	-0.15132	0.3282	0.34647	-0.4246	0.14222	1.3514	0.81653	-0.7528	0.29355	1.7314	1.0411
5e+12	-0.5164	-0.34608	-0.1182	0.17311	-0.3685	0.14352	1.261	0.76715	-0.2503	0.4896	1.5754	0.78108
1e+13	-0.5071	-0.26358	0.1409	0.28104	0.1054	0.70645	1.3546	0.63681	-0.0355	0.97003	1.6752	0.78893

Device Test: 19.19 CURRENT|EA//5/5/0/0/5/100kHz//@EA_IB


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

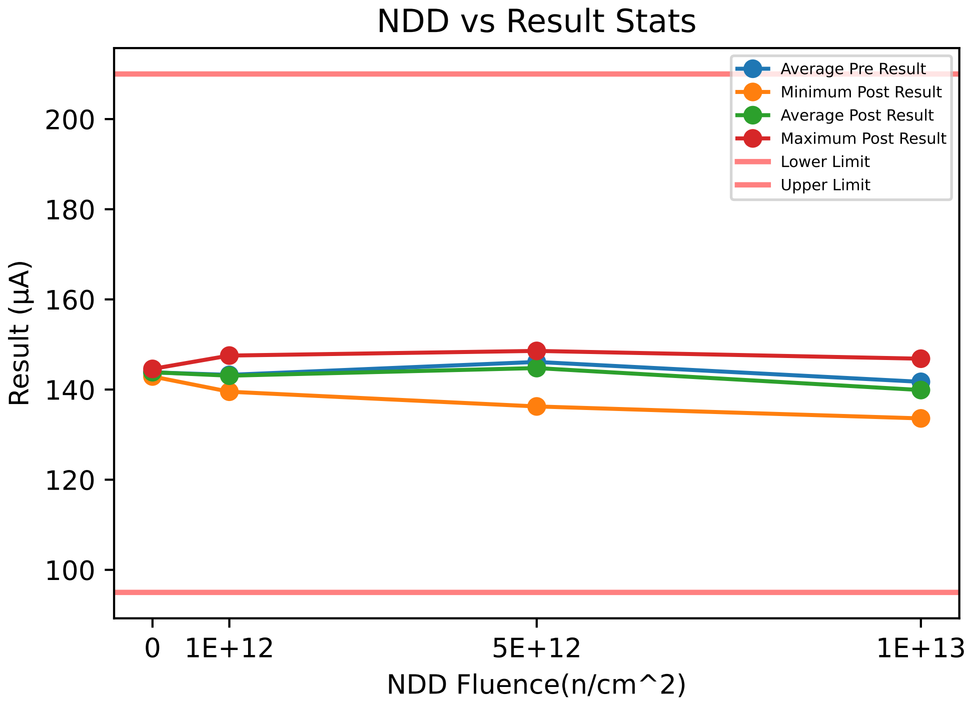
Test Results (Upper Limit = 25.0 (nA))

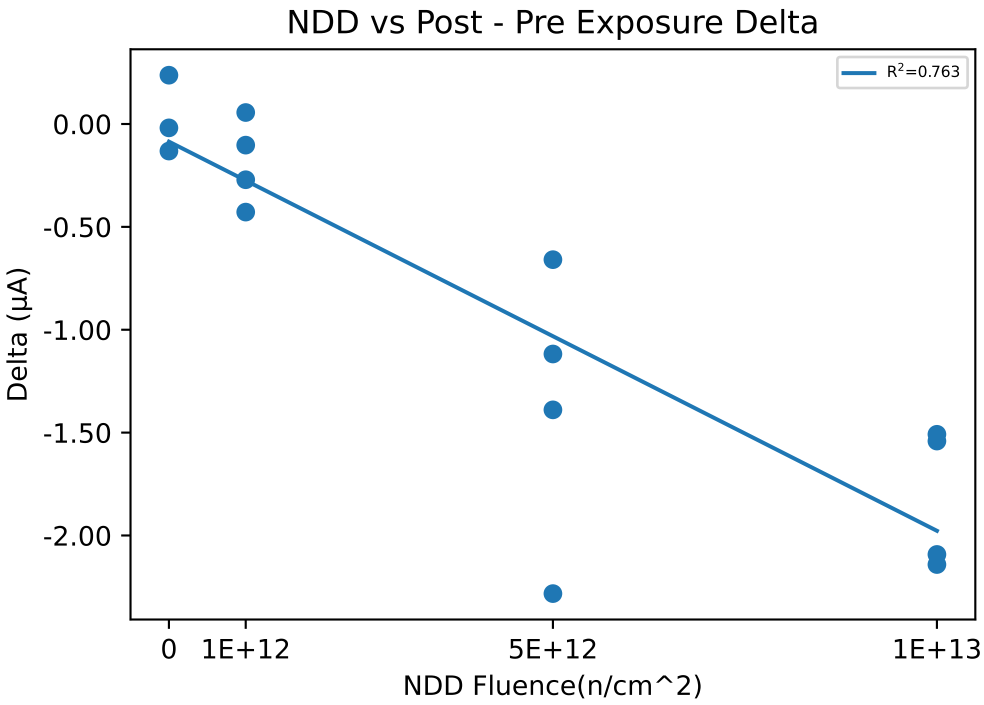
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3843	-0.0629	-0.4472
2	1e+12	NDD	-0.2574	-0.2482	0.0092
3	1e+12	NDD	-0.3113	1.2735	1.5848
4	1e+12	NDD	-0.2899	0.0743	0.3642
5	5e+12	NDD	-0.6038	0.2326	0.8364
6	5e+12	NDD	-0.38	1.367	1.747
7	5e+12	NDD	-0.2587	-0.222	0.0367
8	5e+12	NDD	-0.4727	-0.2326	0.2401
9	1e+13	NDD	-0.2801	1.1269	1.407
10	1e+13	NDD	-0.0058	0.1304	0.1362
11	1e+13	NDD	-0.4665	0.1983	0.6648
12	1e+13	NDD	-0.355	1.2454	1.6004
13	0	CORRELATION	0.556	-0.4371	-0.9931
14	0	CORRELATION	-0.3916	-0.4823	-0.0907
15	0	CORRELATION	-0.355	1.2953	1.6503

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3916	-0.063533	0.556	0.53684	-0.4823	0.1253	1.2953	1.0135	-0.9931	0.18883	1.6503	1.3437
1e+12	-0.3113	-0.11858	0.3843	0.33598	-0.2482	0.25918	1.2735	0.68901	-0.4472	0.37775	1.5848	0.87054
5e+12	-0.6038	-0.4288	-0.2587	0.14591	-0.2326	0.28625	1.367	0.75242	0.0367	0.71505	1.747	0.76711
1e+13	-0.4665	-0.27685	-0.0058	0.19626	0.1304	0.67525	1.2454	0.59257	0.1362	0.9521	1.6004	0.67712

Device Test: 19.2 CURRENT|EA_SOURCE//4.5/4.5/0/0/4.5/500kHz//@EA_I_SOURCE





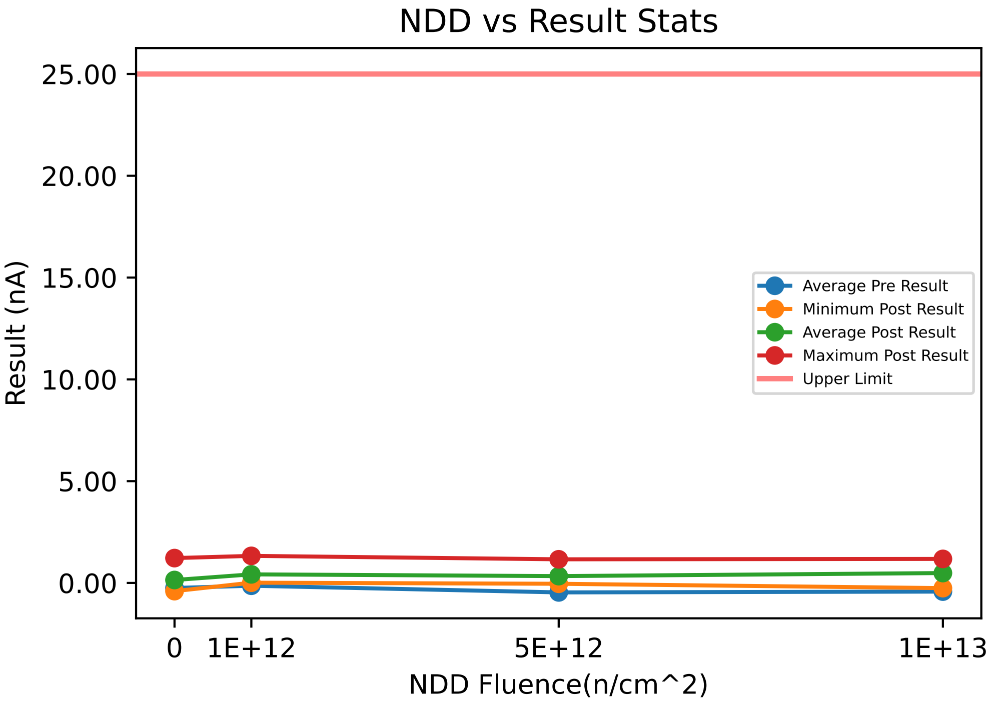
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

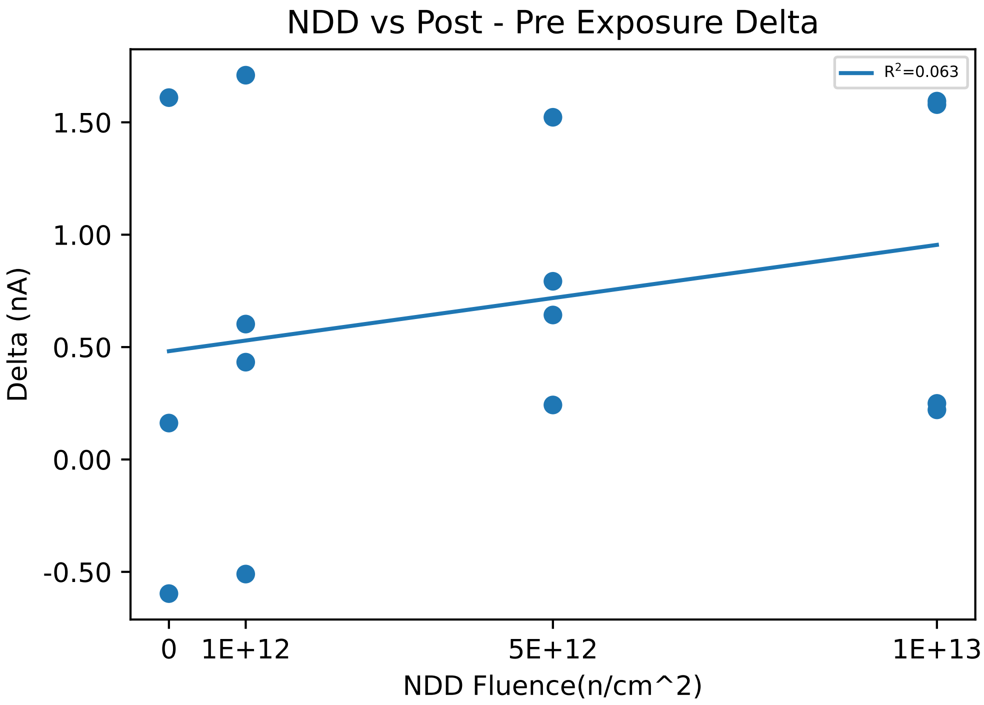
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	144.29	144.18	-0.1027
2	1e+12	NDD	139.95	139.52	-0.4282
3	1e+12	NDD	147.48	147.54	0.0558
4	1e+12	NDD	141.31	141.04	-0.2709
5	5e+12	NDD	149.69	148.57	-1.1179
6	5e+12	NDD	149.46	148.07	-1.3894
7	5e+12	NDD	146.82	146.17	-0.6594
8	5e+12	NDD	138.53	136.25	-2.2825
9	1e+13	NDD	135.14	133.6	-1.5411
10	1e+13	NDD	138.24	136.73	-1.5082
11	1e+13	NDD	148.93	146.84	-2.0922
12	1e+13	NDD	144.53	142.39	-2.1412
13	0	CORRELATION	142.66	142.9	0.2372
14	0	CORRELATION	144.6	144.58	-0.0188
15	0	CORRELATION	144.18	144.05	-0.1315

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	142.66	143.81	144.6	1.0221	142.9	143.84	144.58	0.8618	-0.1315	0.028967	0.2372	0.18893
1e+12	139.95	143.26	147.48	3.3493	139.52	143.07	147.54	3.5559	-0.4282	-0.1865	0.0558	0.20918
5e+12	138.53	146.13	149.69	5.2263	136.25	144.77	148.57	5.7694	-2.2825	-1.3623	-0.6594	0.68345
1e+13	135.14	141.71	148.93	6.2015	133.6	139.89	146.84	5.8922	-2.1412	-1.8207	-1.5082	0.34267

Device Test: 19.20 CURRENT|EA//5/5/0/0/5/1MHz//@EA_IB





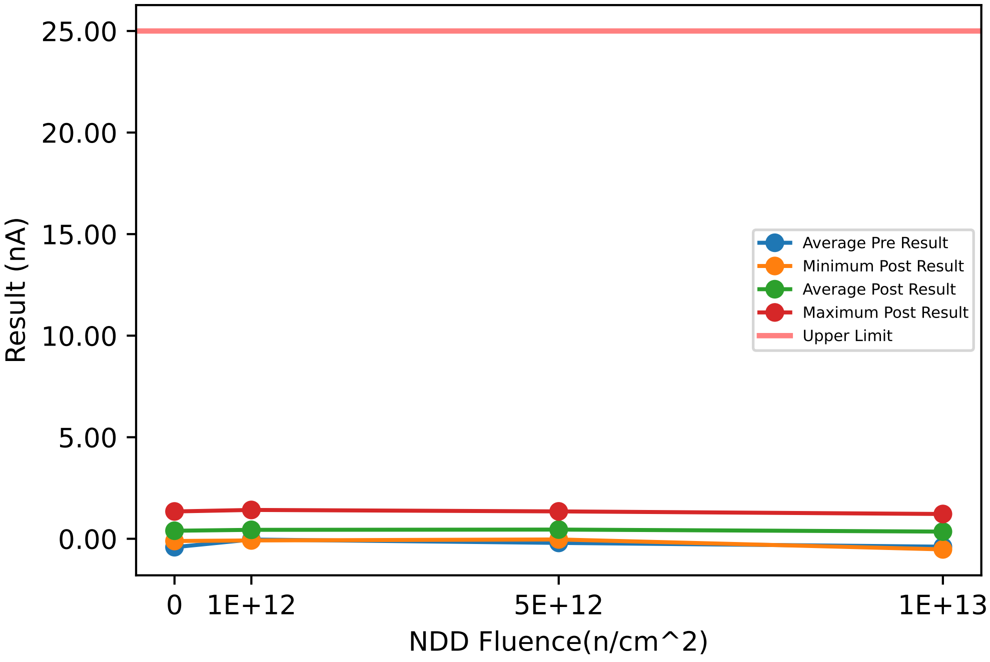
Test Results (Upper Limit = 25.0 (nA))

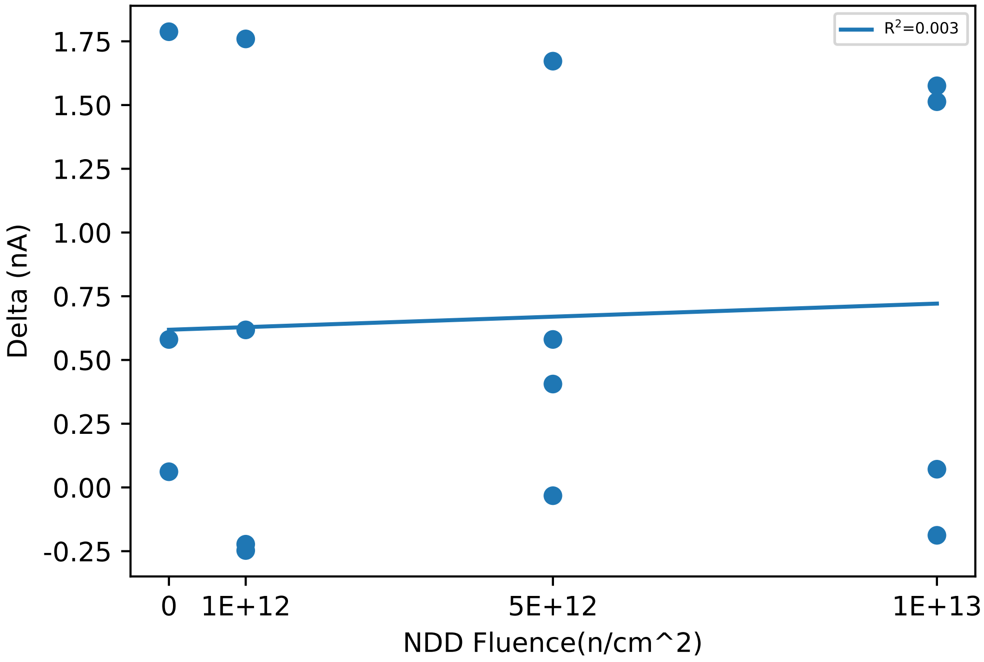
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5217	0.0119	-0.5098
2	1e+12	NDD	-0.3323	0.2701	0.6024
3	1e+12	NDD	-0.38	1.3296	1.7096
4	1e+12	NDD	-0.3586	0.0743	0.4329
5	5e+12	NDD	-0.5788	0.2139	0.7927
6	5e+12	NDD	-0.3612	1.1612	1.5224
7	5e+12	NDD	-0.2836	-0.0411	0.2425
8	5e+12	NDD	-0.635	0.0078	0.6428
9	1e+13	NDD	-0.4455	1.1488	1.5943
10	1e+13	NDD	-0.3523	-0.1315	0.2208
11	1e+13	NDD	-0.5039	-0.2544	0.2495
12	1e+13	NDD	-0.3987	1.18	1.5787
13	0	CORRELATION	0.1939	-0.4028	-0.5967
14	0	CORRELATION	-0.5476	-0.3856	0.162
15	0	CORRELATION	-0.3893	1.2205	1.6098

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5476	-0.24767	0.1939	0.39051	-0.4028	0.14403	1.2205	0.93229	-0.5967	0.3917	1.6098	1.121
1e+12	-0.38	-0.1373	0.5217	0.43977	0.0119	0.42147	1.3296	0.61533	-0.5098	0.55878	1.7096	0.90994
5e+12	-0.635	-0.46465	-0.2836	0.16885	-0.0411	0.33545	1.1612	0.56148	0.2425	0.8001	1.5224	0.53461
1e+13	-0.5039	-0.4251	-0.3523	0.064865	-0.2544	0.48572	1.18	0.78537	0.2208	0.91082	1.5943	0.78032

Device Test: 19.21 CURRENT|EA//12/12/0/0/5/100kHz//@EA_IB


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

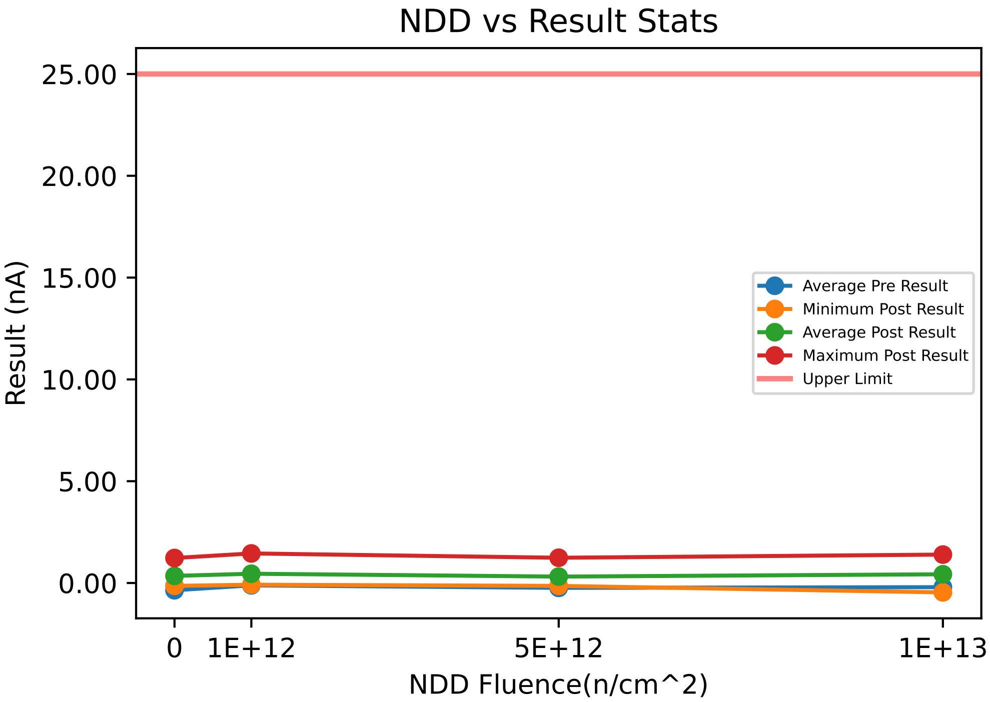
Test Results (Upper Limit = 25.0 (nA))

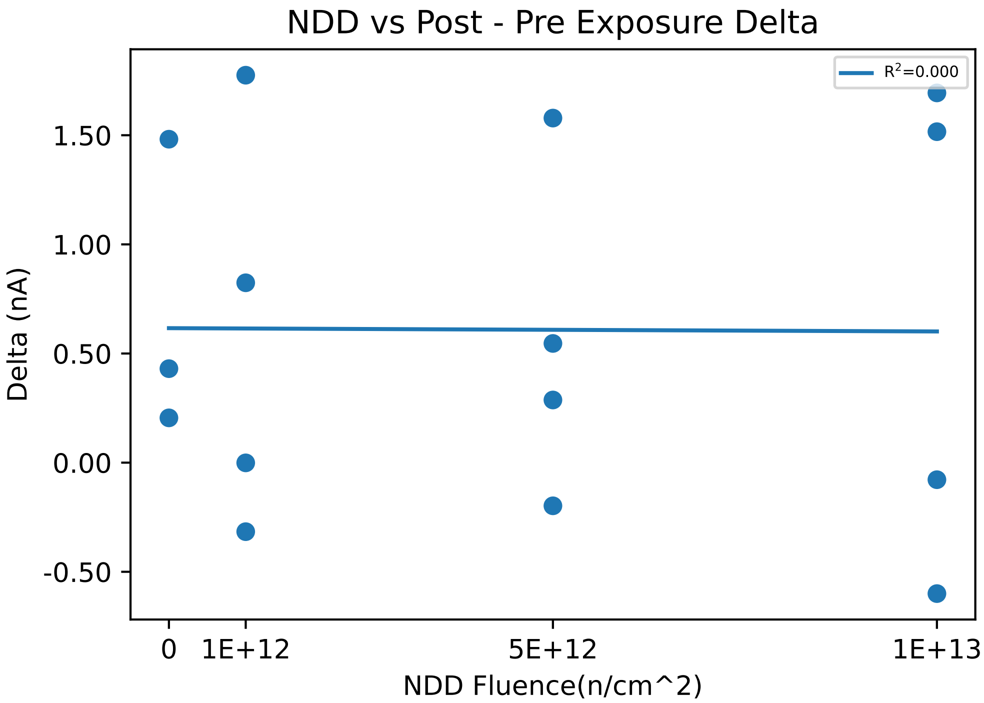
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3126	0.0899	-0.2227
2	1e+12	NDD	-0.2855	0.3325	0.618
3	1e+12	NDD	-0.3394	1.42	1.7594
4	1e+12	NDD	0.1658	-0.0816	-0.2474
5	5e+12	NDD	-0.4384	-0.0328	0.4056
6	5e+12	NDD	-0.3238	1.3483	1.6721
7	5e+12	NDD	0.2782	0.2458	-0.0324
8	5e+12	NDD	-0.3292	0.2513	0.5805
9	1e+13	NDD	-0.355	1.2205	1.5755
10	1e+13	NDD	-0.2431	-0.4309	-0.1878
11	1e+13	NDD	-0.5944	-0.5229	0.0715
12	1e+13	NDD	-0.3643	1.1488	1.5131
13	0	CORRELATION	-0.1713	-0.1097	0.0616
14	0	CORRELATION	-0.6288	-0.0484	0.5804
15	0	CORRELATION	-0.4424	1.3452	1.7876

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6288	-0.41417	-0.1713	0.23005	-0.1097	0.3957	1.3452	0.82286	0.0616	0.80987	1.7876	0.88558
1e+12	-0.3394	-0.036625	0.3126	0.32483	-0.0816	0.4402	1.42	0.67493	-0.2474	0.47682	1.7594	0.94495
5e+12	-0.4384	-0.2033	0.2782	0.32531	-0.0328	0.45315	1.3483	0.61133	-0.0324	0.65645	1.6721	0.72451
1e+13	-0.5944	-0.3892	-0.2431	0.14747	-0.5229	0.35387	1.2205	0.96048	-0.1878	0.74307	1.5755	0.93156

Device Test: 19.22 CURRENT|EA//12/12/0/0/5/1MHz//@EA_IB





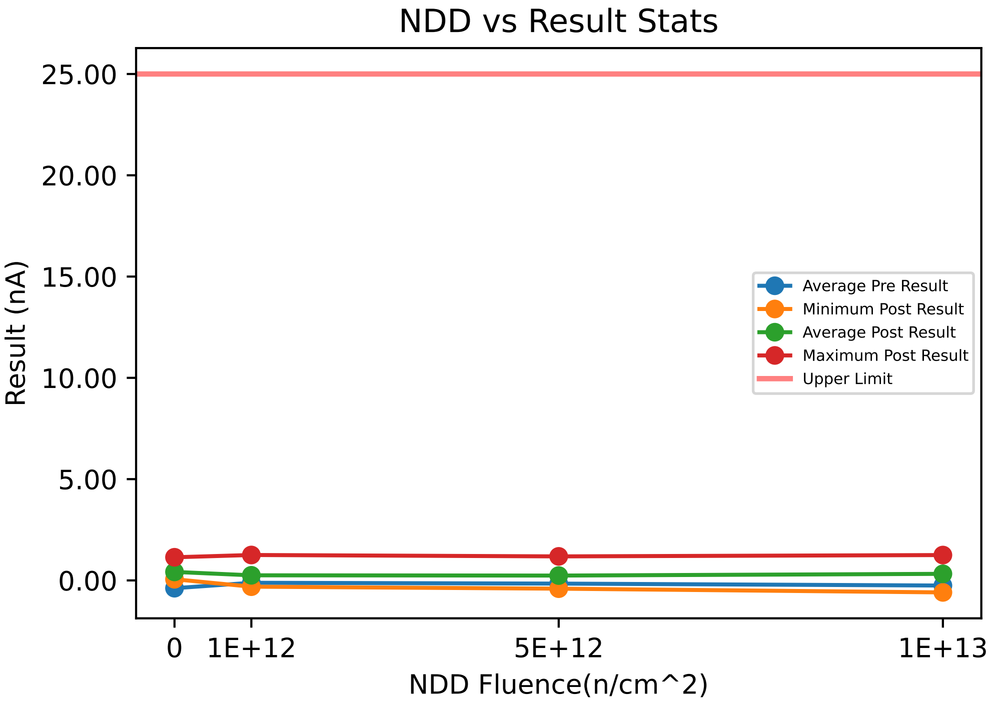
Test Results (Upper Limit = 25.0 (nA))

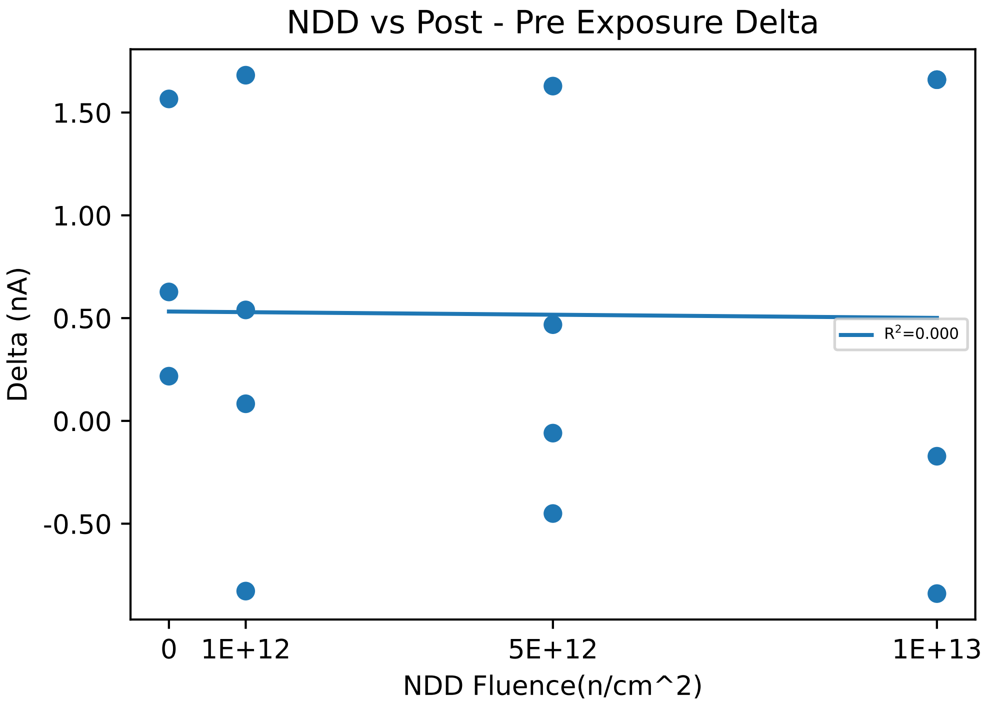
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0909	0.0899	-0.001
2	1e+12	NDD	-0.4634	0.3606	0.824
3	1e+12	NDD	-0.3238	1.4512	1.775
4	1e+12	NDD	0.2314	-0.0848	-0.3162
5	5e+12	NDD	-0.4291	-0.142	0.2871
6	5e+12	NDD	-0.3394	1.2392	1.5786
7	5e+12	NDD	0.2938	0.0961	-0.1977
8	5e+12	NDD	-0.4821	0.064	0.5461
9	1e+13	NDD	-0.3394	1.1768	1.5162
10	1e+13	NDD	0.1378	-0.4621	-0.5999
11	1e+13	NDD	-0.3199	-0.398	-0.0781
12	1e+13	NDD	-0.2988	1.3951	1.6939
13	0	CORRELATION	-0.3461	-0.1409	0.2052
14	0	CORRELATION	-0.4696	-0.039	0.4306
15	0	CORRELATION	-0.2551	1.2267	1.4818

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4696	-0.35693	-0.2551	0.10766	-0.1409	0.34893	1.2267	0.76187	0.2052	0.70587	1.4818	0.68136
1e+12	-0.4634	-0.11622	0.2314	0.33033	-0.0848	0.45422	1.4512	0.68945	-0.3162	0.57045	1.775	0.93594
5e+12	-0.4821	-0.2392	0.2938	0.36018	-0.142	0.31433	1.2392	0.62554	-0.1977	0.55353	1.5786	0.7497
1e+13	-0.3394	-0.20508	0.1378	0.22918	-0.4621	0.42795	1.3951	0.99508	-0.5999	0.63302	1.6939	1.1447

Device Test: 19.23 CURRENT|EA//14/14/0/0/5/100kHz//@EA_IB





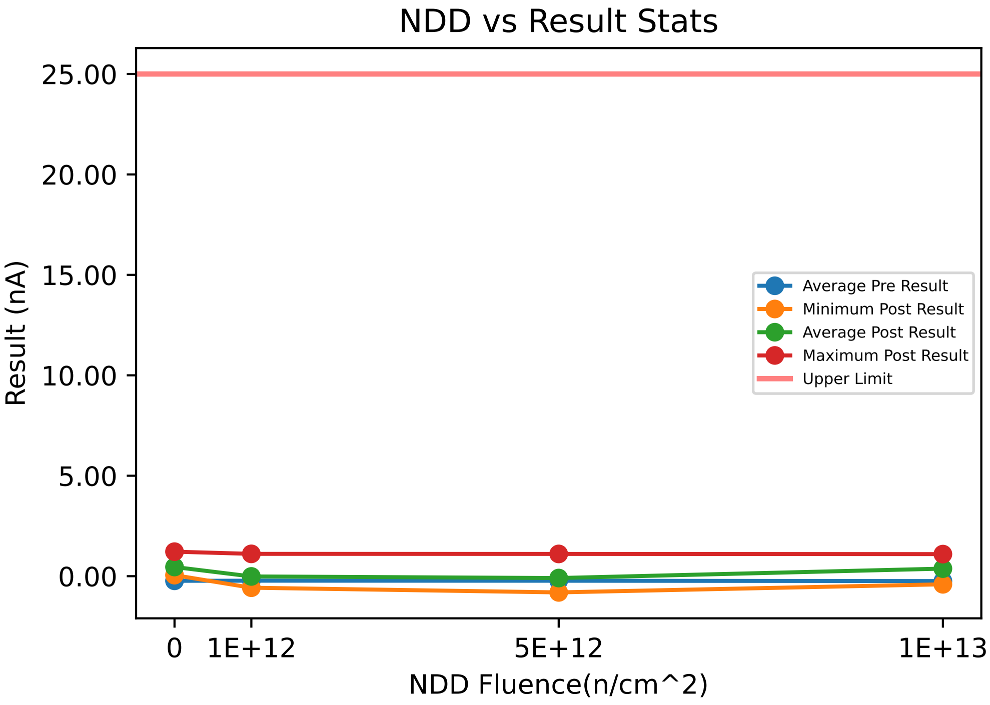
Test Results (Upper Limit = 25.0 (nA))

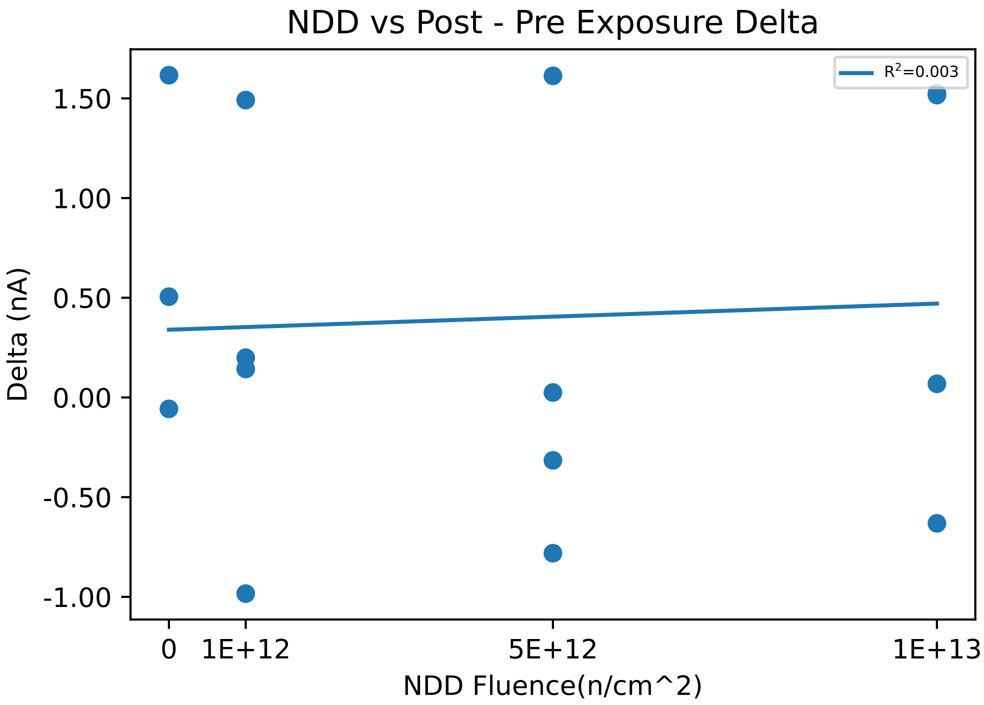
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.0433	0.04	0.0833
2	1e+12	NDD	-0.5164	0.0234	0.5398
3	1e+12	NDD	-0.4268	1.2548	1.6816
4	1e+12	NDD	0.5186	-0.3093	-0.8279
5	5e+12	NDD	-0.3479	-0.4074	-0.0595
6	5e+12	NDD	-0.4424	1.1862	1.6286
7	5e+12	NDD	0.5529	0.1023	-0.4506
8	5e+12	NDD	-0.3916	0.0765	0.4681
9	1e+13	NDD	-0.4674	1.1924	1.6598
10	1e+13	NDD	0.2845	-0.5556	-0.8401
11	1e+13	NDD	-0.4197	-0.5916	-0.1719
12	1e+13	NDD	-0.408	1.2517	1.6597
13	0	CORRELATION	-0.1588	0.0587	0.2175
14	0	CORRELATION	-0.5695	0.0578	0.6273
15	0	CORRELATION	-0.4237	1.1425	1.5662

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5695	-0.384	-0.1588	0.20821	0.0578	0.41967	1.1425	0.62599	0.2175	0.80367	1.5662	0.69143
1e+12	-0.5164	-0.11697	0.5186	0.47078	-0.3093	0.25222	1.2548	0.68748	-0.8279	0.3692	1.6816	1.0434
5e+12	-0.4424	-0.15725	0.5529	0.47501	-0.4074	0.2394	1.1862	0.67333	-0.4506	0.39665	1.6286	0.90346
1e+13	-0.4674	-0.25265	0.2845	0.35902	-0.5916	0.32422	1.2517	1.0371	-0.8401	0.57688	1.6598	1.2798

Device Test: 19.24 CURRENT|EA//14/14/0/0/5/1MHz//@EA_IB





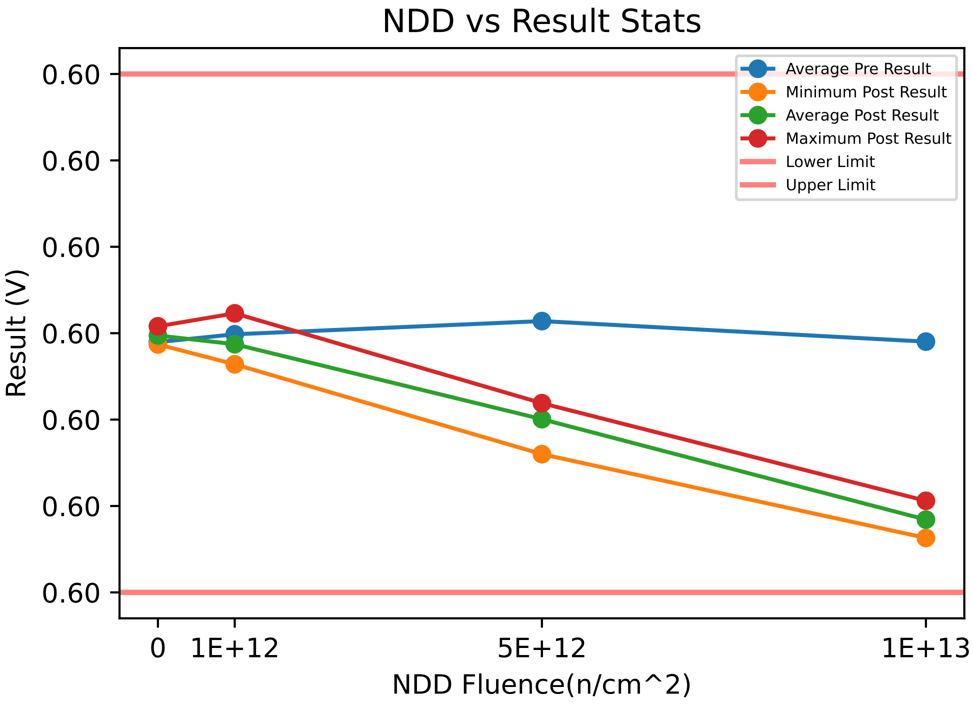
Test Results (Upper Limit = 25.0 (nA))

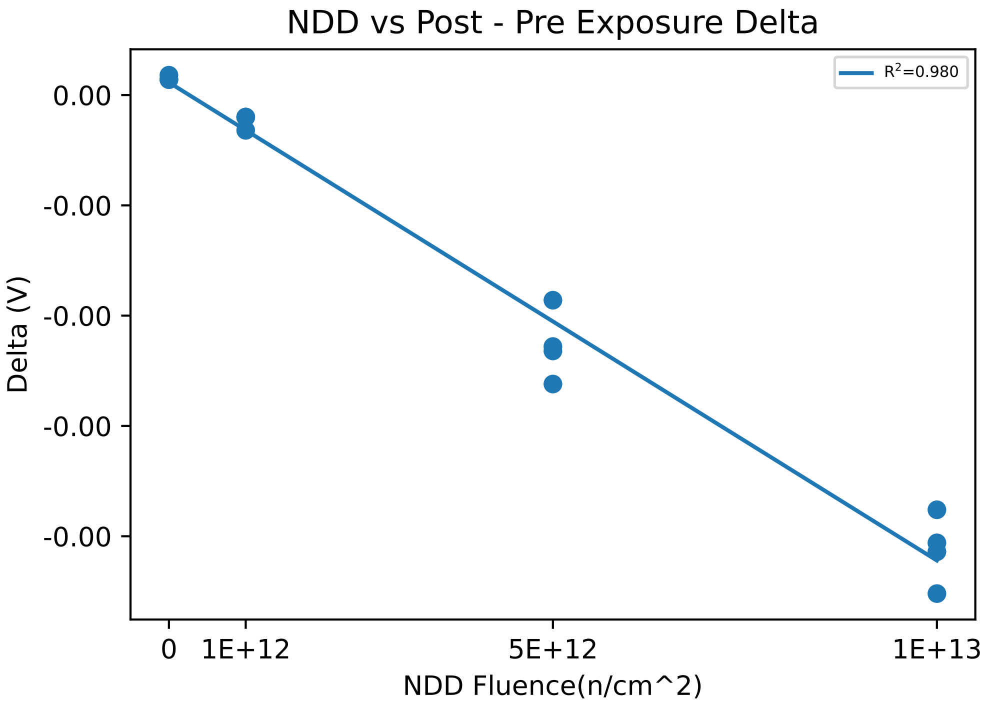
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	-0.318	-0.1752	0.1428
2	1e+12	NDD	-0.61	-0.4105	0.1995
3	1e+12	NDD	-0.38	1.1114	1.4914
4	1e+12	NDD	0.4093	-0.5743	-0.9836
5	5e+12	NDD	-0.4915	-0.807	-0.3155
6	5e+12	NDD	-0.5048	1.1082	1.613
7	5e+12	NDD	0.4905	-0.2906	-0.7811
8	5e+12	NDD	-0.4041	-0.3793	0.0248
9	1e+13	NDD	-0.4268	1.0989	1.5257
10	1e+13	NDD	0.4218	-0.2095	-0.6313
11	1e+13	NDD	-0.4727	-0.4043	0.0684
12	1e+13	NDD	-0.4955	1.0209	1.5164
13	0	CORRELATION	0.1565	0.0992	-0.0573
14	0	CORRELATION	-0.454	0.0515	0.5055
15	0	CORRELATION	-0.3956	1.2205	1.6161

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.454	-0.23103	0.1565	0.33688	0.0515	0.45707	1.2205	0.66158	-0.0573	0.6881	1.6161	0.85151
1e+12	-0.61	-0.22468	0.4093	0.44092	-0.5743	-0.01215	1.1114	0.76673	-0.9836	0.21253	1.4914	1.0118
5e+12	-0.5048	-0.22748	0.4905	0.48073	-0.807	-0.092175	1.1082	0.8314	-0.7811	0.1353	1.613	1.039
1e+13	-0.4955	-0.2433	0.4218	0.44432	-0.4043	0.3765	1.0989	0.79376	-0.6313	0.6198	1.5257	1.0792

Device Test: 19.25 VOLTAGE|VREF//4.5/4.5/0/0/4.5/100kHz//@VREF_25C





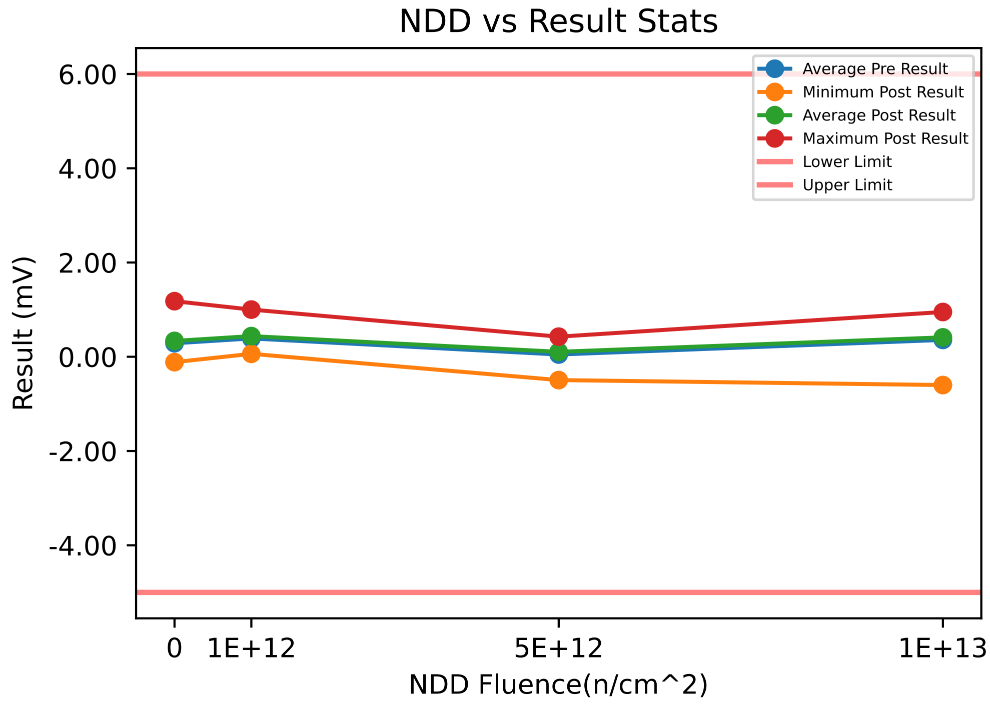
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

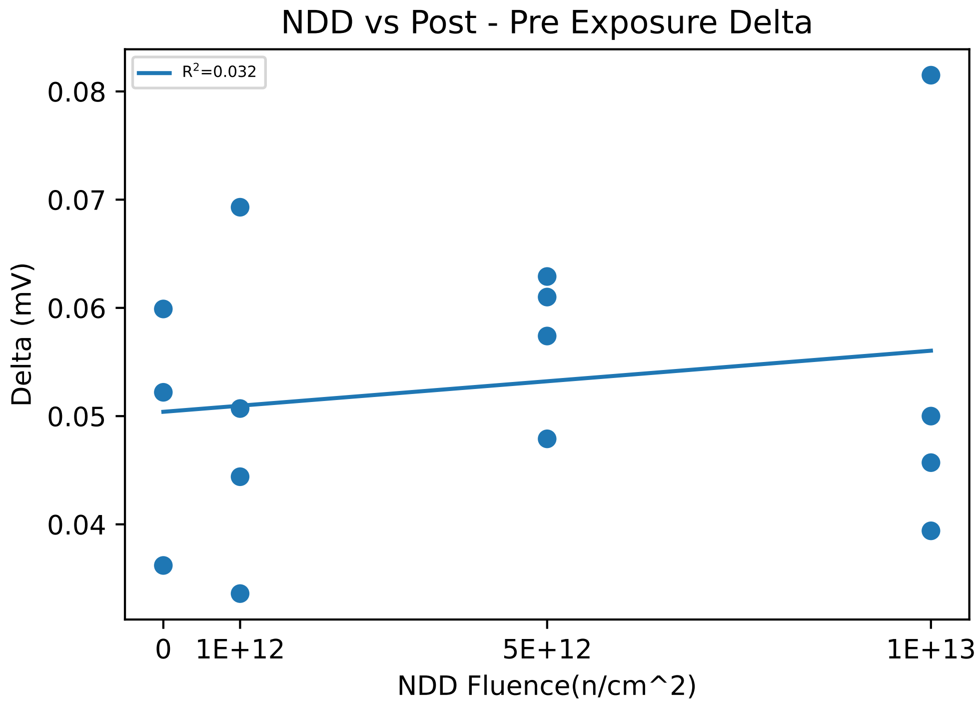
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59974	0.59964	-0.0001
2	1e+12	NDD	0.59995	0.59985	-0.0001
3	1e+12	NDD	0.59993	0.59977	-0.00016
4	1e+12	NDD	0.60033	0.60023	-0.0001
5	5e+12	NDD	0.60025	0.59909	-0.00116
6	5e+12	NDD	0.60028	0.59914	-0.00114
7	5e+12	NDD	0.60012	0.59919	-0.00093
8	5e+12	NDD	0.59991	0.5986	-0.00131
9	1e+13	NDD	0.59998	0.59791	-0.00207
10	1e+13	NDD	0.5998	0.59777	-0.00203
11	1e+13	NDD	0.59994	0.59806	-0.00188
12	1e+13	NDD	0.59989	0.59763	-0.00226
13	0	CORRELATION	0.5998	0.59987	7e-05
14	0	CORRELATION	0.5999	0.59997	7e-05
15	0	CORRELATION	0.59999	0.60008	9e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.59999	9.5044e-05	0.59987	0.59997	0.60008	0.00010504	7e-05	7.6667e-05	9e-05	1.1547e-05
1e+12	0.59974	0.59999	0.60033	0.00024717	0.59964	0.59987	0.60023	0.00025356	-0.00016	-0.000115	-0.0001	3e-05
5e+12	0.59991	0.60014	0.60028	0.00016833	0.5986	0.59901	0.59919	0.00027307	-0.00131	-0.001135	-0.00093	0.00015631
1e+13	0.5998	0.5999	0.59998	7.7621e-05	0.59763	0.59784	0.59806	0.00018464	-0.00226	-0.00206	-0.00188	0.00015642

Device Test: 19.27 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/100kHz//@EA_OS





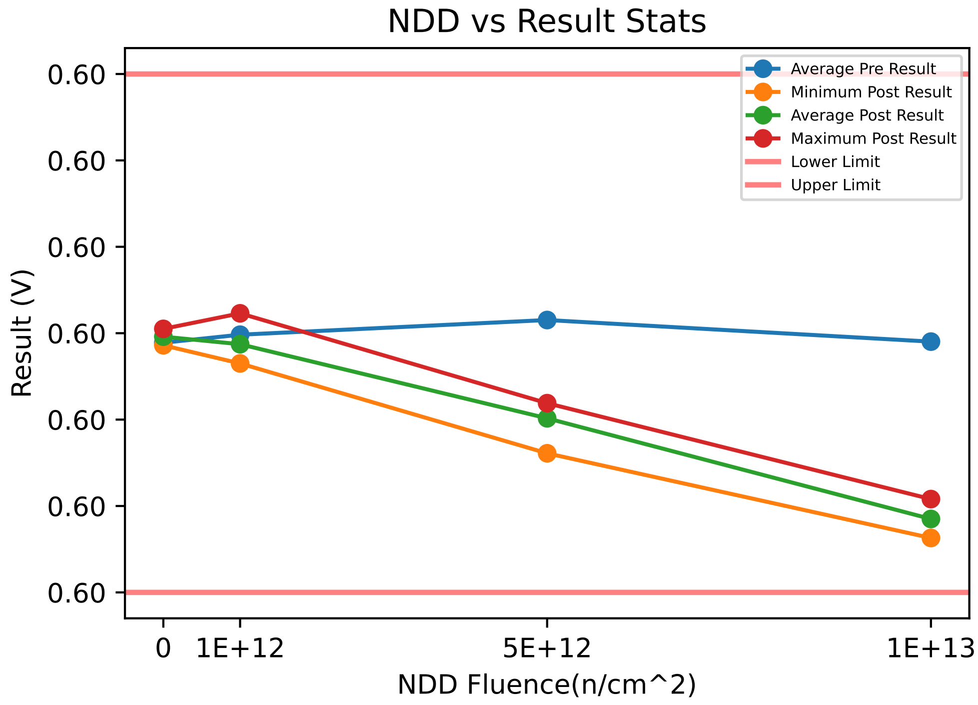
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

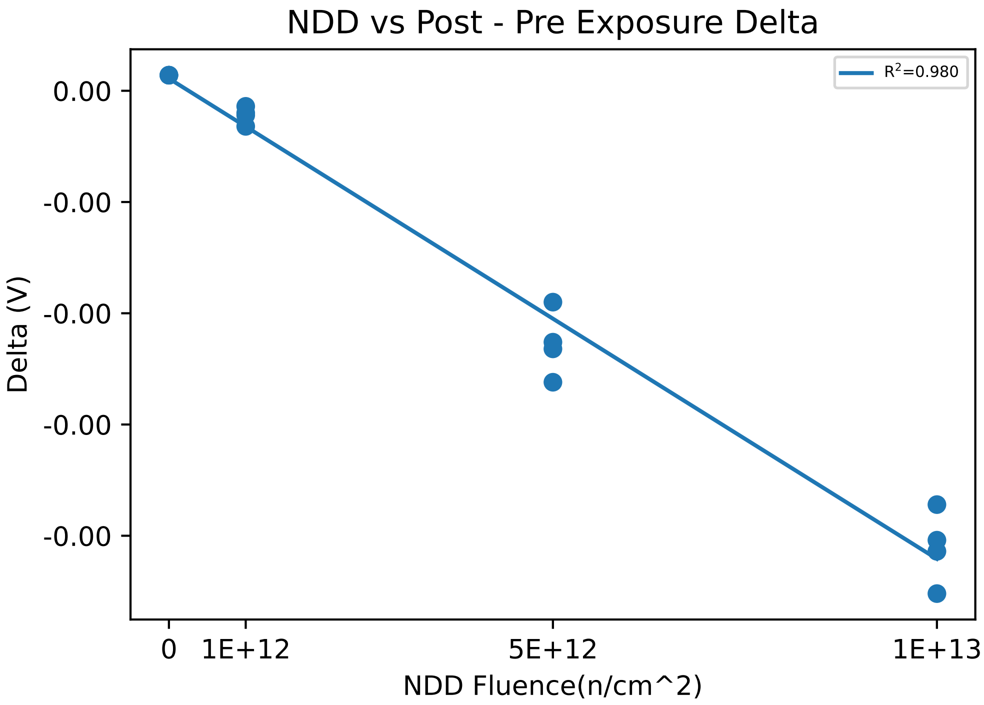
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3491	0.3935	0.0444
2	1e+12	NDD	0.2452	0.2959	0.0507
3	1e+12	NDD	0.9674	1.001	0.0336
4	1e+12	NDD	-0.007	0.0623	0.0693
5	5e+12	NDD	0.1515	0.2144	0.0629
6	5e+12	NDD	-0.5523	-0.4949	0.0574
7	5e+12	NDD	0.2134	0.2744	0.061
8	5e+12	NDD	0.3785	0.4264	0.0479
9	1e+13	NDD	0.8998	0.9498	0.05
10	1e+13	NDD	0.5772	0.6587	0.0815
11	1e+13	NDD	0.5991	0.6385	0.0394
12	1e+13	NDD	-0.6459	-0.6002	0.0457
13	0	CORRELATION	1.1195	1.1794	0.0599
14	0	CORRELATION	-0.0931	-0.0569	0.0362
15	0	CORRELATION	-0.1665	-0.1143	0.0522

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1665	0.28663	1.1195	0.72222	-0.1143	0.33607	1.1794	0.73091	0.0362	0.049433	0.0599	0.01209
1e+12	-0.007	0.38868	0.9674	0.41378	0.0623	0.43817	1.001	0.40012	0.0336	0.0495	0.0693	0.01497
5e+12	-0.5523	0.047775	0.3785	0.41136	-0.4949	0.10508	0.4264	0.40981	0.0479	0.0573	0.0629	0.0066688
1e+13	-0.6459	0.35755	0.8998	0.68497	-0.6002	0.4117	0.9498	0.68943	0.0394	0.05415	0.0815	0.018746

Device Test: 19.28 VOLTAGE|VREF//5/5/0/0/5/100kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

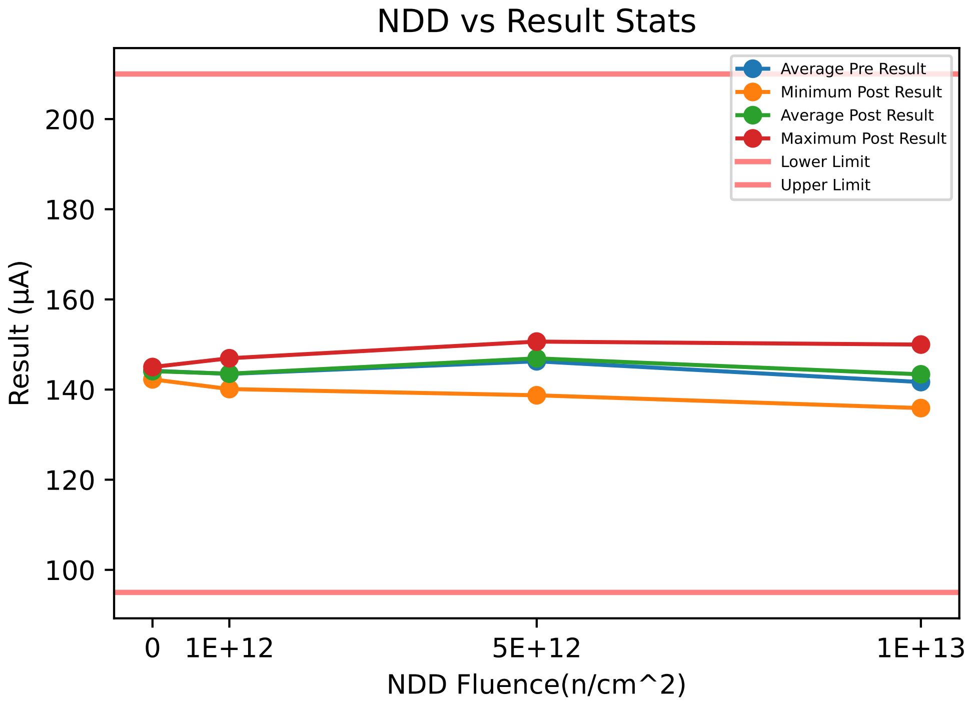
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

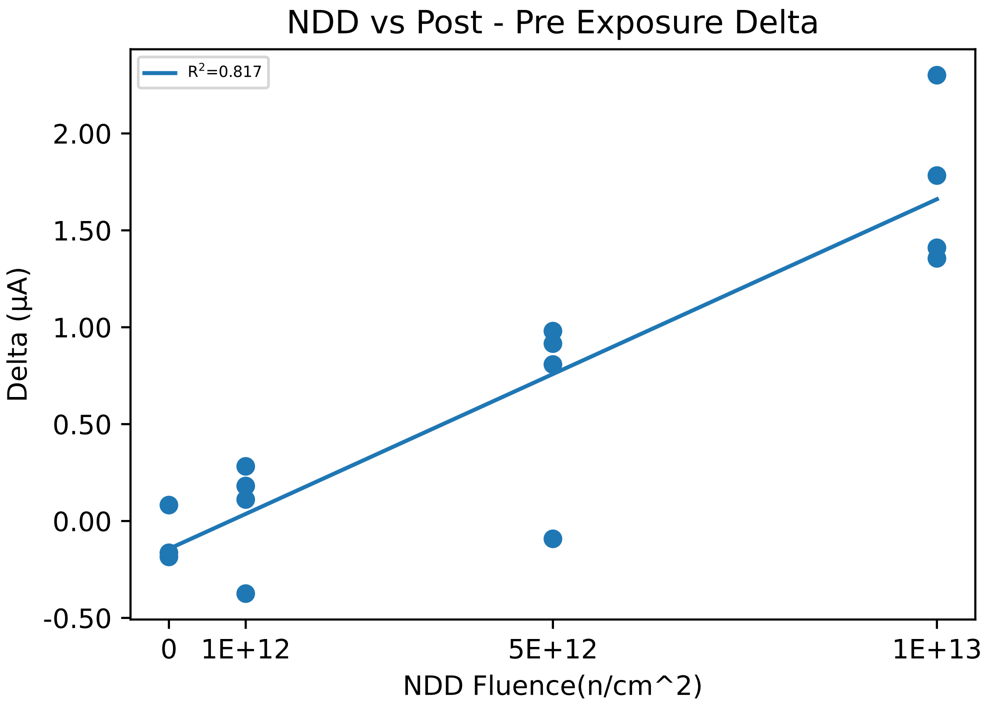
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59972	0.59965	-7e-05
2	1e+12	NDD	0.59995	0.59985	-0.0001
3	1e+12	NDD	0.59992	0.59976	-0.00016
4	1e+12	NDD	0.60034	0.60023	-0.00011
5	5e+12	NDD	0.60026	0.5991	-0.00116
6	5e+12	NDD	0.60029	0.59916	-0.00113
7	5e+12	NDD	0.60014	0.59919	-0.00095
8	5e+12	NDD	0.59992	0.59861	-0.00131
9	1e+13	NDD	0.59998	0.59791	-0.00207
10	1e+13	NDD	0.5998	0.59778	-0.00202
11	1e+13	NDD	0.59994	0.59808	-0.00186
12	1e+13	NDD	0.59989	0.59763	-0.00226
13	0	CORRELATION	0.59979	0.59986	7e-05
14	0	CORRELATION	0.5999	0.59997	7e-05
15	0	CORRELATION	0.59998	0.60005	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59979	0.59989	0.59998	9.5394e-05	0.59986	0.59996	0.60005	9.5394e-05	7e-05	7e-05	7e-05	6.41e-17
1e+12	0.59972	0.59998	0.60034	0.00025928	0.59965	0.59987	0.60023	0.00025198	-0.00016	-0.00011	-7e-05	3.7417e-05
5e+12	0.59992	0.60015	0.60029	0.000168	0.59861	0.59901	0.59919	0.00027258	-0.00131	-0.0011375	-0.00095	0.00014773
1e+13	0.5998	0.5999	0.59998	7.7621e-05	0.59763	0.59785	0.59808	0.00019131	-0.00226	-0.0020525	-0.00186	0.0001648

Device Test: 19.3 CURRENT|EA_SINK//4.5/4.5/0/0/4.5/500kHz//@EA_I_SINK


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

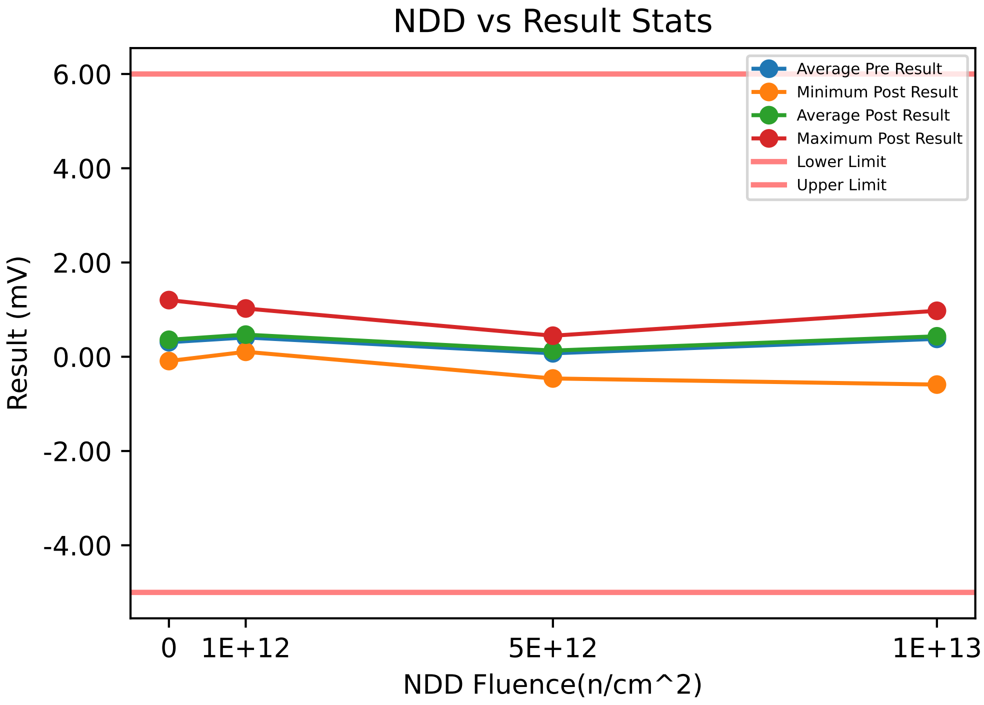
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

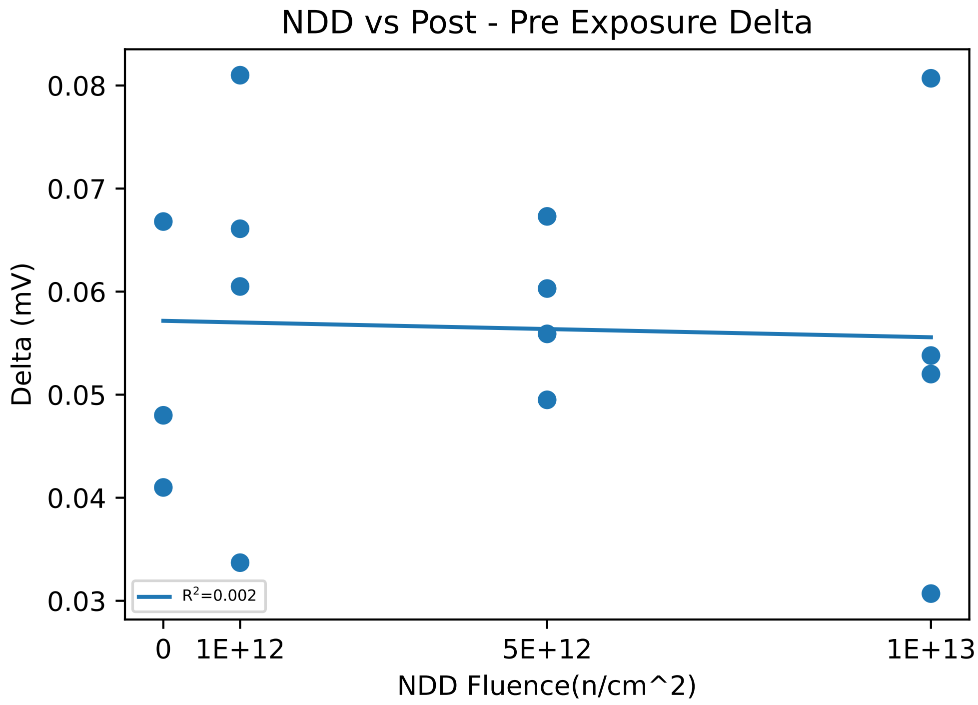
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.22	145.5	0.2821
2	1e+12	NDD	140.48	140.11	-0.3745
3	1e+12	NDD	146.76	146.94	0.1808
4	1e+12	NDD	141.43	141.54	0.111
5	5e+12	NDD	149.72	150.64	0.9155
6	5e+12	NDD	149.59	150.4	0.8078
7	5e+12	NDD	146.94	147.92	0.98
8	5e+12	NDD	138.82	138.73	-0.0919
9	1e+13	NDD	134.48	135.89	1.41
10	1e+13	NDD	138.36	140.66	2.3006
11	1e+13	NDD	148.62	149.98	1.3553
12	1e+13	NDD	145.19	146.97	1.7828
13	0	CORRELATION	142.18	142.26	0.0823
14	0	CORRELATION	145.17	144.98	-0.1852
15	0	CORRELATION	145.16	144.99	-0.164

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	142.18	144.17	145.17	1.7218	142.26	144.08	144.99	1.5735	-0.1852	-0.088967	0.0823	0.1487
1e+12	140.48	143.47	146.76	2.9983	140.11	143.52	146.94	3.224	-0.3745	0.04985	0.2821	0.29149
5e+12	138.82	146.27	149.72	5.1281	138.73	146.92	150.64	5.5984	-0.0919	0.65285	0.98	0.50156
1e+13	134.48	141.66	148.62	6.4139	135.89	143.37	149.98	6.3237	1.3553	1.7122	2.3006	0.43585

Device Test: 19.30 VOLTAGE|OFFSET//5/5/0/0/5/100kHz//@EA_OS





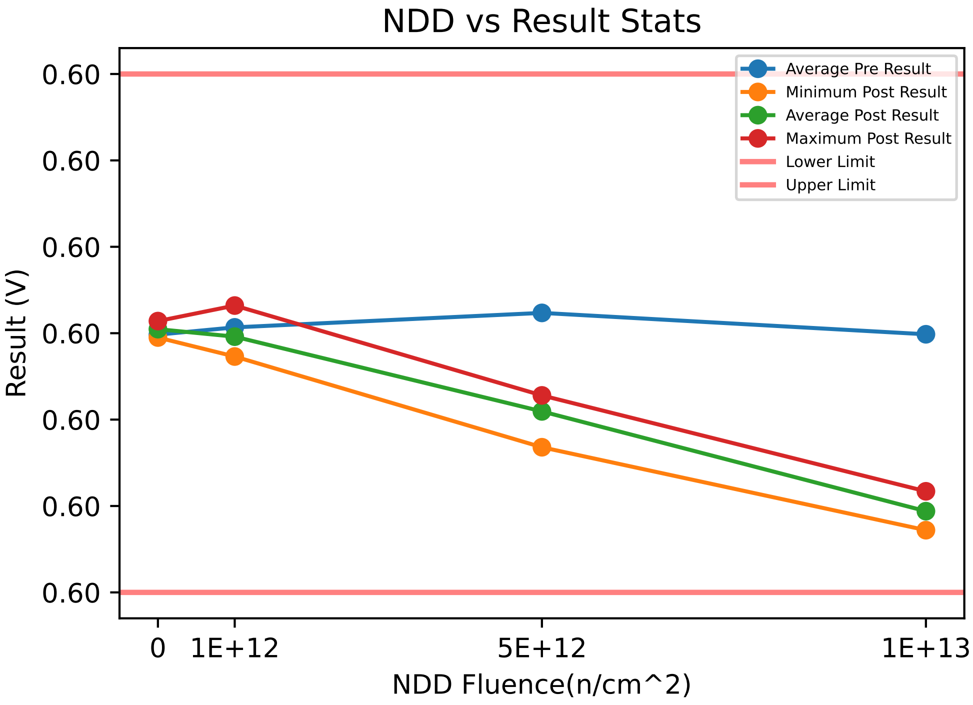
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

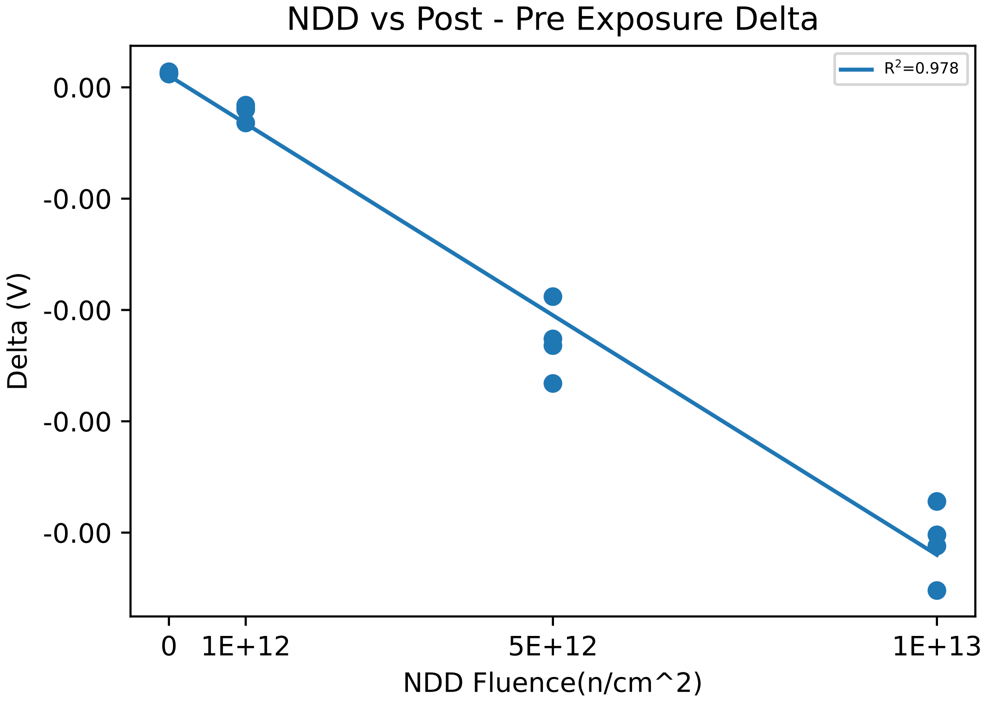
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3579	0.4184	0.0605
2	1e+12	NDD	0.264	0.3301	0.0661
3	1e+12	NDD	0.9907	1.0244	0.0337
4	1e+12	NDD	0.0241	0.1051	0.081
5	5e+12	NDD	0.1914	0.2409	0.0495
6	5e+12	NDD	-0.528	-0.4607	0.0673
7	5e+12	NDD	0.2379	0.2982	0.0603
8	5e+12	NDD	0.3909	0.4468	0.0559
9	1e+13	NDD	0.9232	0.9752	0.052
10	1e+13	NDD	0.6044	0.6851	0.0807
11	1e+13	NDD	0.6128	0.6666	0.0538
12	1e+13	NDD	-0.6208	-0.5901	0.0307
13	0	CORRELATION	1.1358	1.2026	0.0668
14	0	CORRELATION	-0.0726	-0.0316	0.041
15	0	CORRELATION	-0.1386	-0.0906	0.048

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1386	0.3082	1.1358	0.71748	-0.0906	0.36013	1.2026	0.73019	0.041	0.051933	0.0668	0.013342
1e+12	0.0241	0.40918	0.9907	0.41237	0.1051	0.4695	1.0244	0.39274	0.0337	0.060325	0.081	0.019746
5e+12	-0.528	0.07305	0.3909	0.40966	-0.4607	0.1313	0.4468	0.40409	0.0495	0.05825	0.0673	0.0074875
1e+13	-0.6208	0.3799	0.9232	0.68343	-0.5901	0.4342	0.9752	0.69734	0.0307	0.0543	0.0807	0.02049

Device Test: 19.31 VOLTAGE|VREF//12/12/0/0/5/100kHz//@VREF_25C





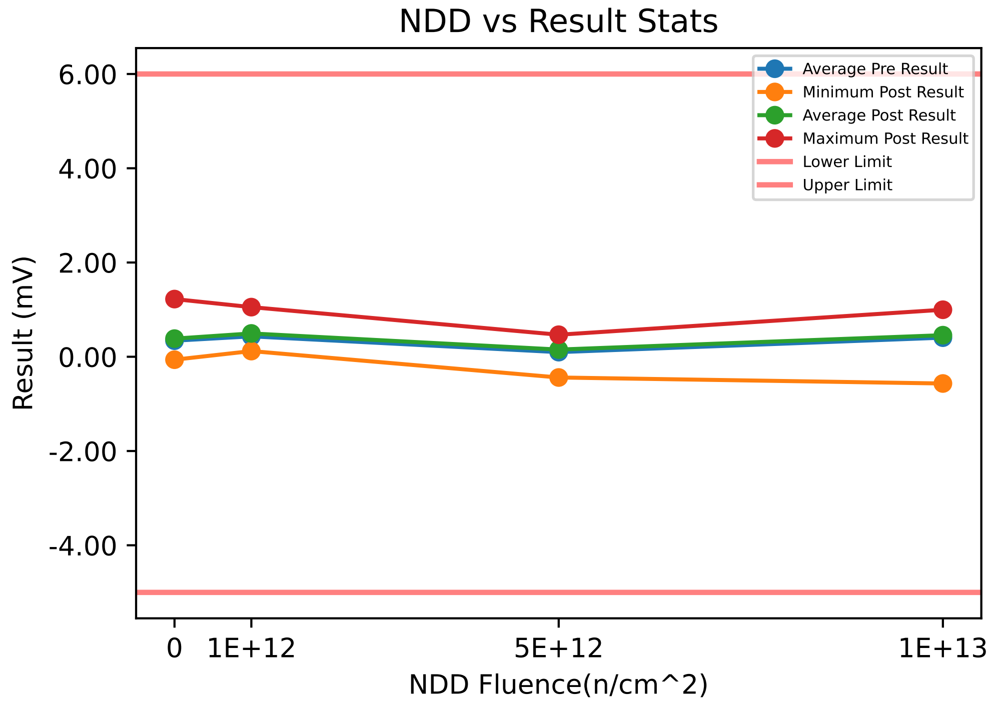
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

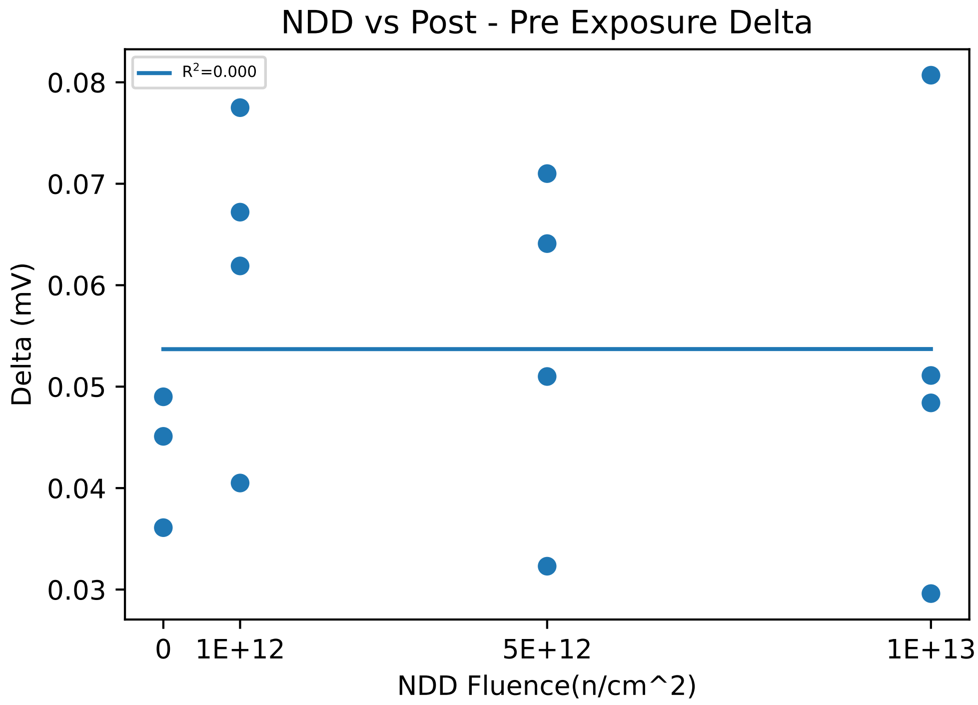
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59981	0.59973	-8e-05
2	1e+12	NDD	0.60004	0.59994	-0.0001
3	1e+12	NDD	0.60001	0.59985	-0.00016
4	1e+12	NDD	0.60041	0.60032	-9e-05
5	5e+12	NDD	0.60034	0.59918	-0.00116
6	5e+12	NDD	0.60037	0.59924	-0.00113
7	5e+12	NDD	0.60022	0.59928	-0.00094
8	5e+12	NDD	0.60001	0.59868	-0.00133
9	1e+13	NDD	0.60006	0.598	-0.00206
10	1e+13	NDD	0.59988	0.59787	-0.00201
11	1e+13	NDD	0.60003	0.59817	-0.00186
12	1e+13	NDD	0.59998	0.59772	-0.00226
13	0	CORRELATION	0.59988	0.59995	7e-05
14	0	CORRELATION	0.59999	0.60005	6e-05
15	0	CORRELATION	0.60008	0.60014	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59988	0.59998	0.60008	0.00010017	0.59995	0.60005	0.60014	9.5044e-05	6e-05	6.3333e-05	7e-05	5.7735e-06
1e+12	0.59981	0.60007	0.60041	0.00025012	0.59973	0.59996	0.60032	0.00025495	-0.00016	-0.0001075	-8e-05	3.594e-05
5e+12	0.60001	0.60023	0.60037	0.0001634	0.59868	0.5991	0.59928	0.0002797	-0.00133	-0.00114	-0.00094	0.00015979
1e+13	0.59988	0.59999	0.60006	7.8899e-05	0.59772	0.59794	0.59817	0.00019131	-0.00226	-0.0020475	-0.00186	0.0001652

Device Test: 19.33 VOLTAGE|OFFSET//12/12/0/0/5/100kHz//@EA_OS





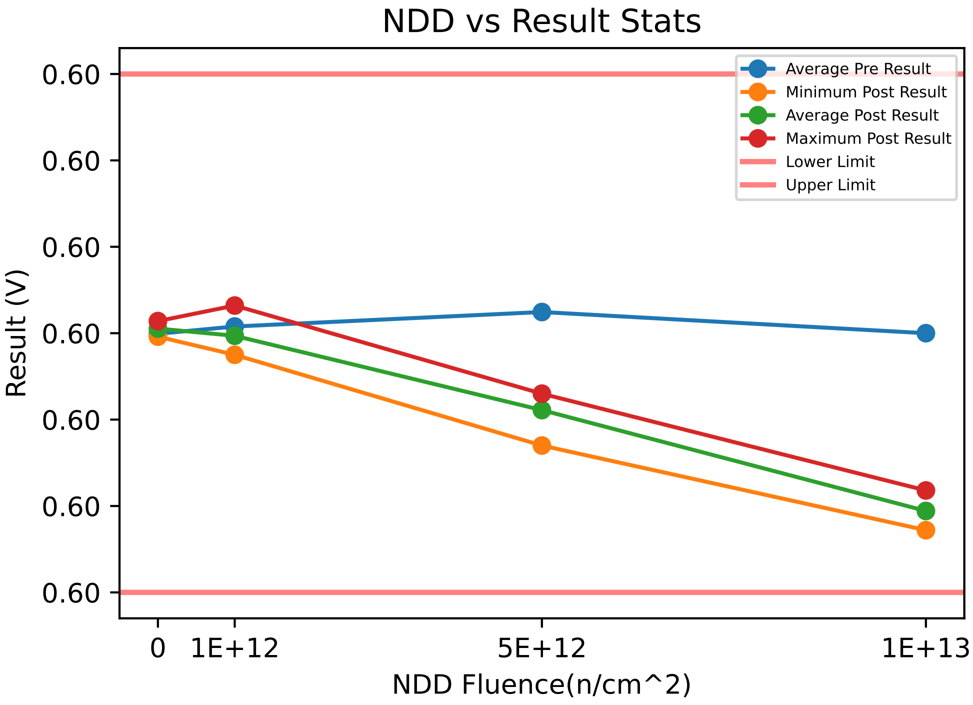
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

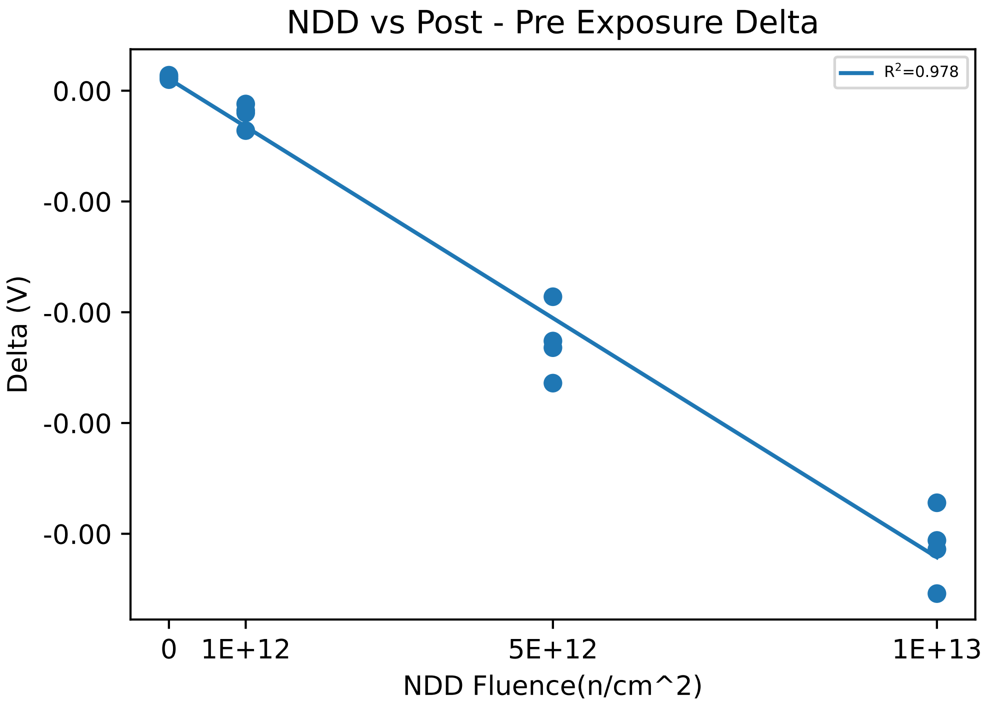
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3788	0.446	0.0672
2	1e+12	NDD	0.2977	0.3596	0.0619
3	1e+12	NDD	1.0128	1.0533	0.0405
4	1e+12	NDD	0.0431	0.1206	0.0775
5	5e+12	NDD	0.2061	0.2571	0.051
6	5e+12	NDD	-0.504	-0.4399	0.0641
7	5e+12	NDD	0.2556	0.3266	0.071
8	5e+12	NDD	0.4352	0.4675	0.0323
9	1e+13	NDD	0.9466	0.9977	0.0511
10	1e+13	NDD	0.6286	0.7093	0.0807
11	1e+13	NDD	0.6431	0.6915	0.0484
12	1e+13	NDD	-0.5968	-0.5672	0.0296
13	0	CORRELATION	1.1789	1.224	0.0451
14	0	CORRELATION	-0.0437	-0.0076	0.0361
15	0	CORRELATION	-0.1112	-0.0622	0.049

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1112	0.34133	1.1789	0.72614	-0.0622	0.38473	1.224	0.72734	0.0361	0.0434	0.049	0.0066159
1e+12	0.0431	0.4331	1.0128	0.41208	0.1206	0.49488	1.0533	0.39691	0.0405	0.061775	0.0775	0.015592
5e+12	-0.504	0.098225	0.4352	0.41337	-0.4399	0.15282	0.4675	0.40473	0.0323	0.0546	0.071	0.017024
1e+13	-0.5968	0.40538	0.9466	0.68401	-0.5672	0.45783	0.9977	0.69761	0.0296	0.05245	0.0807	0.021122

Device Test: 19.34 VOLTAGE|VREF//14/14/0/0/5/100kHz//@VREF_25C





Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

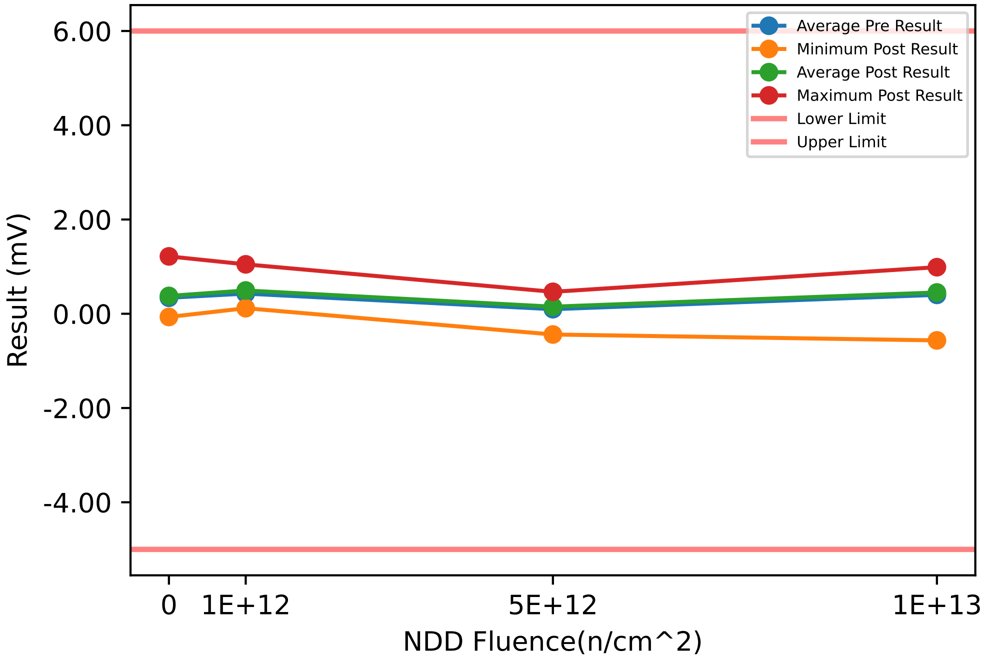
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59981	0.59975	-6e-05
2	1e+12	NDD	0.60005	0.59996	-9e-05
3	1e+12	NDD	0.60003	0.59985	-0.00018
4	1e+12	NDD	0.60042	0.60032	-0.0001
5	5e+12	NDD	0.60035	0.59919	-0.00116
6	5e+12	NDD	0.60038	0.59925	-0.00113
7	5e+12	NDD	0.60023	0.5993	-0.00093
8	5e+12	NDD	0.60002	0.5987	-0.00132
9	1e+13	NDD	0.60008	0.59801	-0.00207
10	1e+13	NDD	0.59989	0.59786	-0.00203
11	1e+13	NDD	0.60004	0.59818	-0.00186
12	1e+13	NDD	0.59999	0.59772	-0.00227
13	0	CORRELATION	0.59989	0.59996	7e-05
14	0	CORRELATION	0.6	0.60006	6e-05
15	0	CORRELATION	0.60009	0.60014	5e-05

Test Statistics (V)

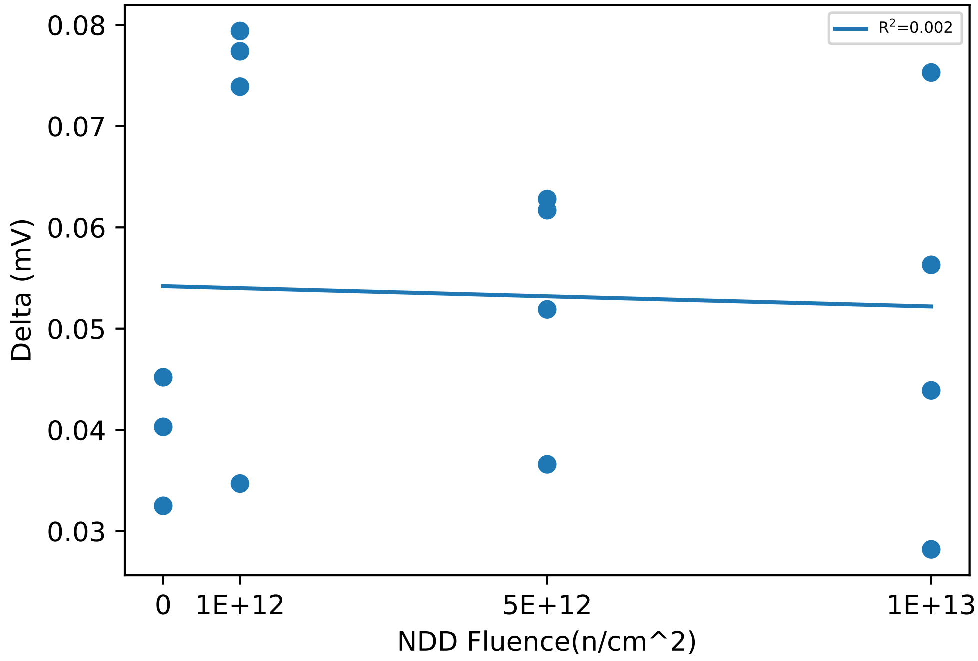
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59989	0.59999	0.60009	0.00010017	0.59996	0.60005	0.60014	9.0185e-05	5e-05	6e-05	7e-05	1e-05
1e+12	0.59981	0.60008	0.60042	0.0002529	0.59975	0.59997	0.60032	0.0002486	-0.00018	-0.0001075	-6e-05	5.1235e-05
5e+12	0.60002	0.60025	0.60038	0.0001634	0.5987	0.59911	0.5993	0.00027701	-0.00132	-0.001135	-0.00093	0.0001601
1e+13	0.59989	0.6	0.60008	8.2057e-05	0.59772	0.59794	0.59818	0.00019772	-0.00227	-0.0020575	-0.00186	0.0001684

Device Test: 19.36 VOLTAGE|OFFSET//14/14/0/0/5/100kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



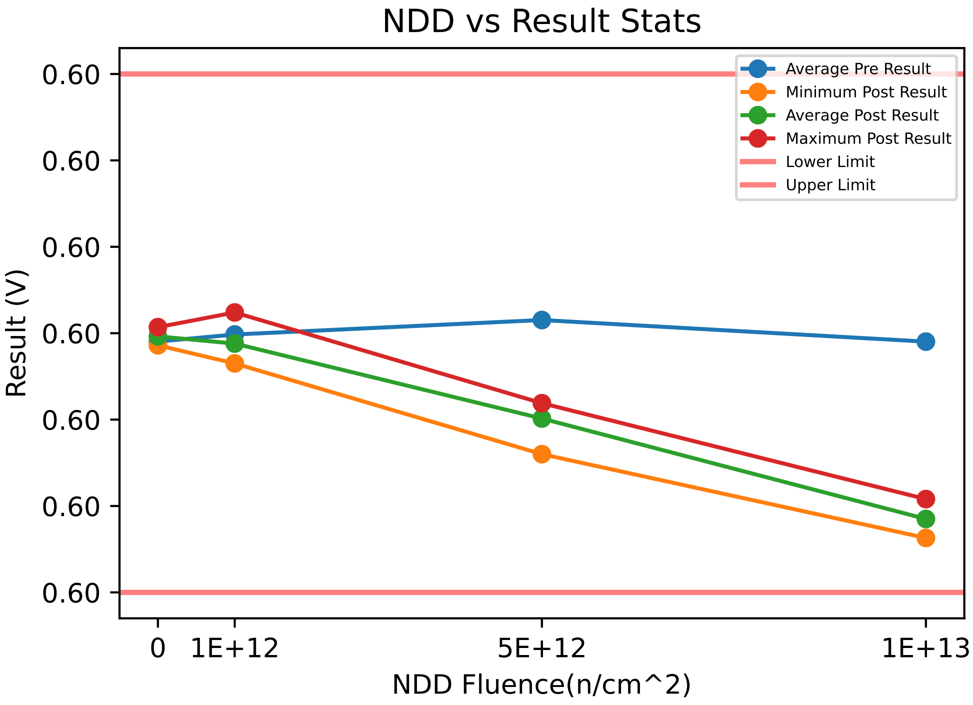
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

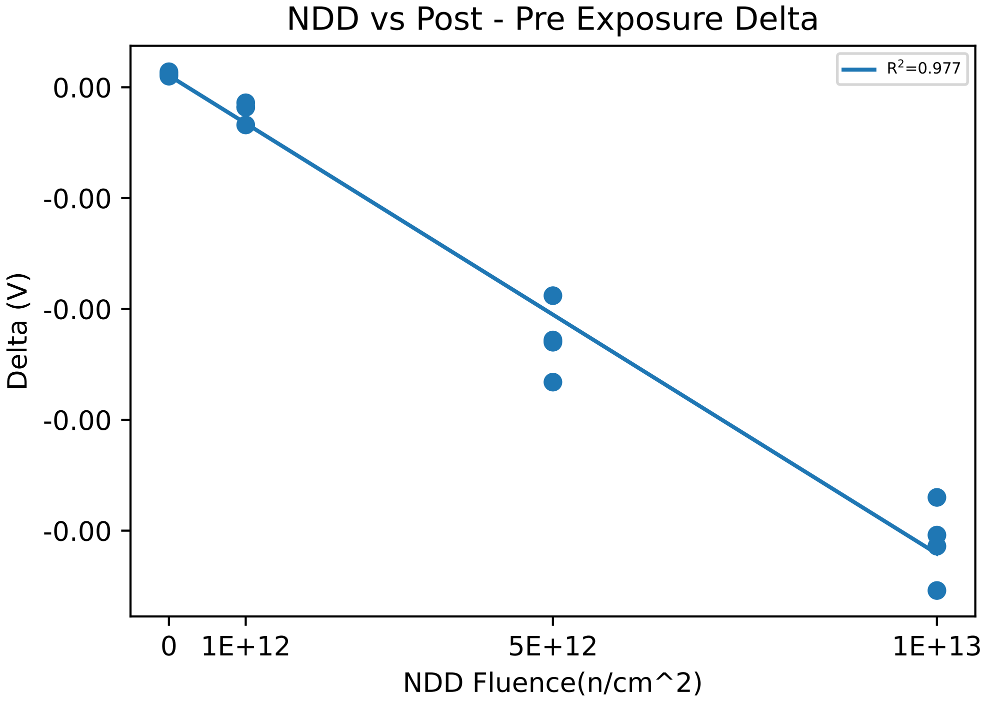
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3671	0.4445	0.0774
2	1e+12	NDD	0.291	0.3649	0.0739
3	1e+12	NDD	1.0139	1.0486	0.0347
4	1e+12	NDD	0.0387	0.1181	0.0794
5	5e+12	NDD	0.2028	0.2547	0.0519
6	5e+12	NDD	-0.503	-0.4402	0.0628
7	5e+12	NDD	0.2599	0.3216	0.0617
8	5e+12	NDD	0.429	0.4656	0.0366
9	1e+13	NDD	0.9444	0.9883	0.0439
10	1e+13	NDD	0.6214	0.6967	0.0753
11	1e+13	NDD	0.631	0.6873	0.0563
12	1e+13	NDD	-0.5933	-0.5651	0.0282
13	0	CORRELATION	1.1772	1.2175	0.0403
14	0	CORRELATION	-0.0463	-0.0138	0.0325
15	0	CORRELATION	-0.1132	-0.068	0.0452

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1132	0.33923	1.1772	0.72647	-0.068	0.37857	1.2175	0.72704	0.0325	0.039333	0.0452	0.0064049
1e+12	0.0387	0.42767	1.0139	0.41526	0.1181	0.49403	1.0486	0.39497	0.0347	0.06635	0.0794	0.021222
5e+12	-0.503	0.097175	0.429	0.41148	-0.4402	0.15043	0.4656	0.40346	0.0366	0.05325	0.0628	0.012133
1e+13	-0.5933	0.40087	0.9444	0.67956	-0.5651	0.4518	0.9883	0.69218	0.0282	0.050925	0.0753	0.019907

Device Test: 19.37 VOLTAGE|VREF//4.5/4.5/0/0/4.5/500kHz//@VREF_25C





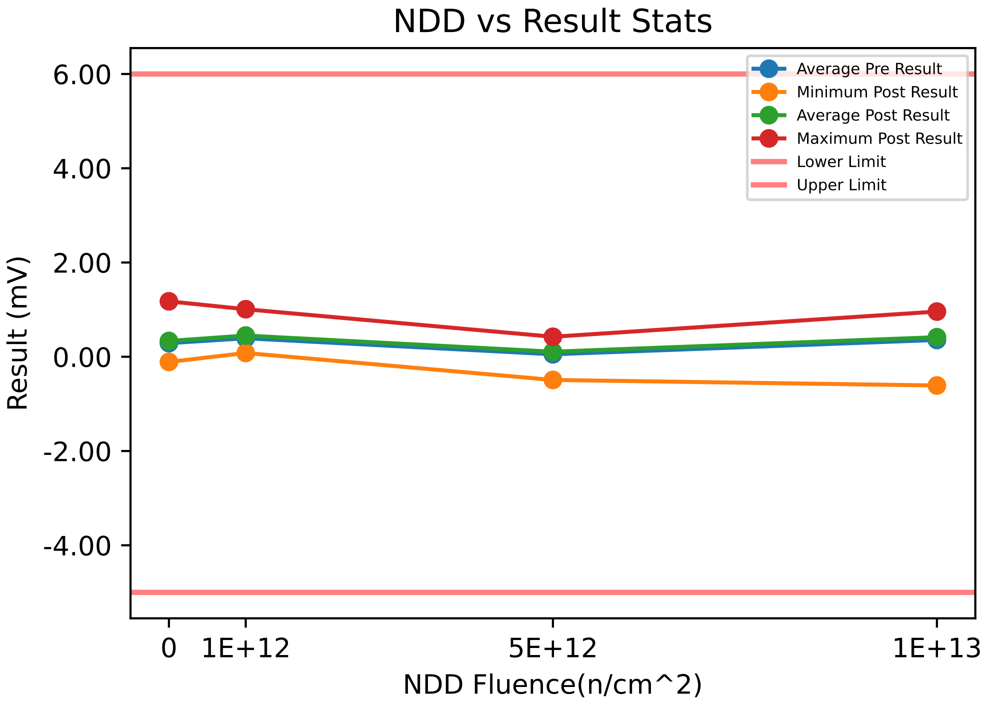
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

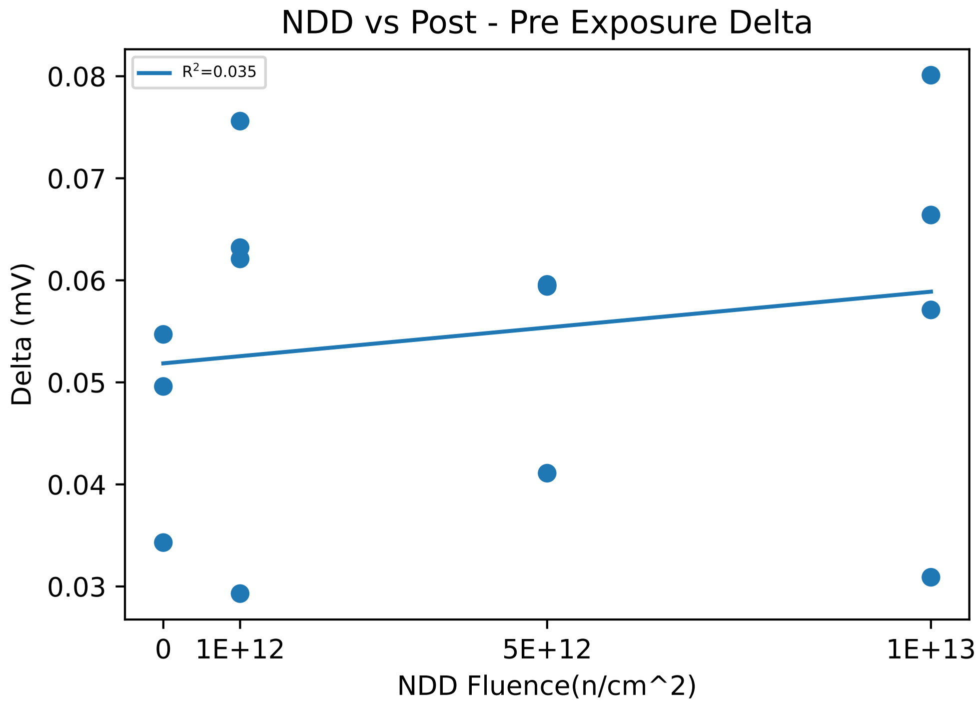
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59972	0.59965	-7e-05
2	1e+12	NDD	0.59995	0.59986	-9e-05
3	1e+12	NDD	0.59994	0.59977	-0.00017
4	1e+12	NDD	0.60033	0.60024	-9e-05
5	5e+12	NDD	0.60026	0.59911	-0.00115
6	5e+12	NDD	0.60029	0.59915	-0.00114
7	5e+12	NDD	0.60013	0.59919	-0.00094
8	5e+12	NDD	0.59993	0.5986	-0.00133
9	1e+13	NDD	0.59998	0.59791	-0.00207
10	1e+13	NDD	0.5998	0.59778	-0.00202
11	1e+13	NDD	0.59993	0.59808	-0.00185
12	1e+13	NDD	0.5999	0.59763	-0.00227
13	0	CORRELATION	0.5998	0.59986	6e-05
14	0	CORRELATION	0.59991	0.59996	5e-05
15	0	CORRELATION	0.6	0.60007	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.6	0.00010017	0.59986	0.59996	0.60007	0.00010504	5e-05	6e-05	7e-05	1e-05
1e+12	0.59972	0.59998	0.60033	0.00025331	0.59965	0.59988	0.60024	0.00025495	-0.00017	-0.000105	-7e-05	4.4347e-05
5e+12	0.59993	0.60015	0.60029	0.00016378	0.5986	0.59901	0.59919	0.00027693	-0.00133	-0.00114	-0.00094	0.00015937
1e+13	0.5998	0.5999	0.59998	7.5884e-05	0.59763	0.59785	0.59808	0.00019131	-0.00227	-0.0020525	-0.00185	0.00017289

Device Test: 19.39 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/500kHz//@EA_OS





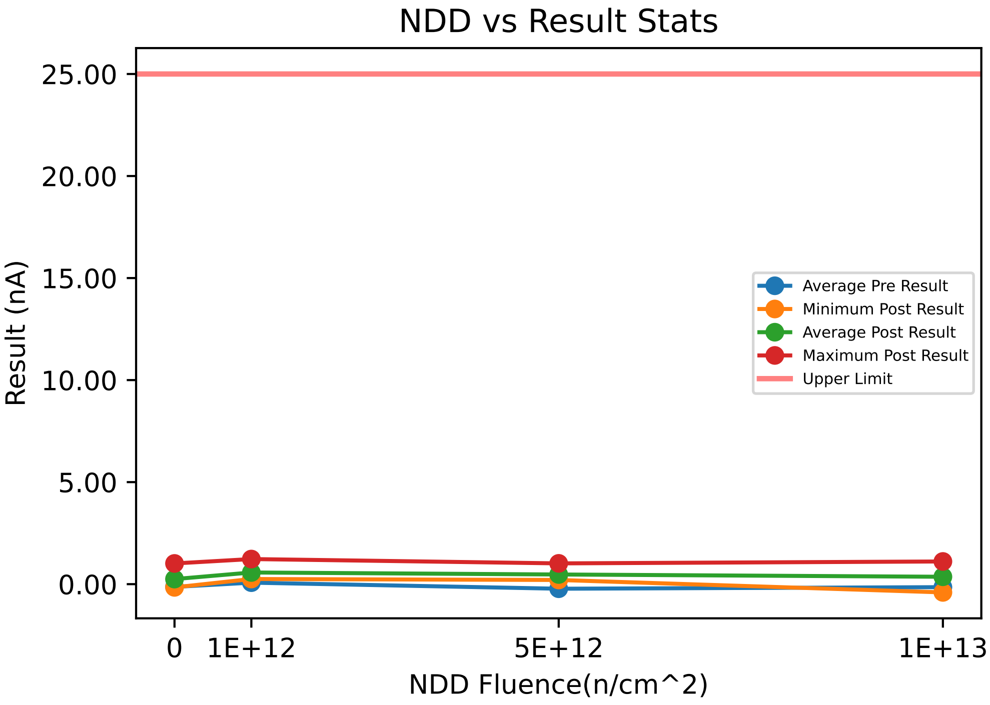
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

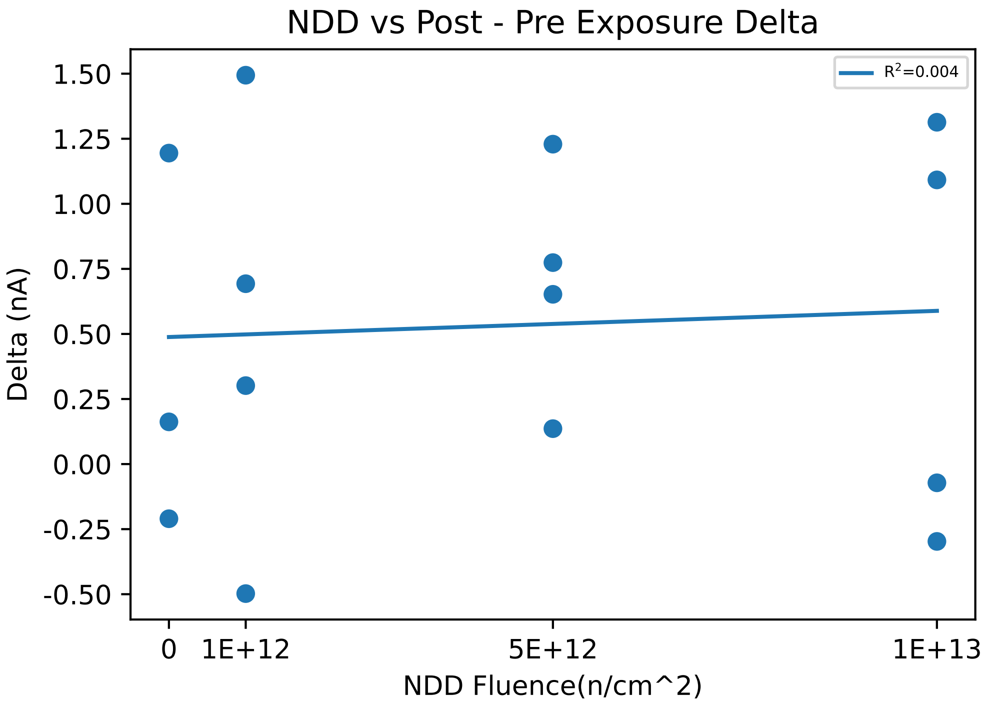
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3399	0.4031	0.0632
2	1e+12	NDD	0.2463	0.3084	0.0621
3	1e+12	NDD	0.9794	1.0087	0.0293
4	1e+12	NDD	0.0048	0.0804	0.0756
5	5e+12	NDD	0.1589	0.2184	0.0595
6	5e+12	NDD	-0.5516	-0.492	0.0596
7	5e+12	NDD	0.2183	0.2777	0.0594
8	5e+12	NDD	0.3832	0.4243	0.0411
9	1e+13	NDD	0.8923	0.9587	0.0664
10	1e+13	NDD	0.5838	0.6639	0.0801
11	1e+13	NDD	0.5898	0.6469	0.0571
12	1e+13	NDD	-0.6404	-0.6095	0.0309
13	0	CORRELATION	1.1215	1.1762	0.0547
14	0	CORRELATION	-0.0947	-0.0604	0.0343
15	0	CORRELATION	-0.1595	-0.1099	0.0496

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1595	0.2891	1.1215	0.72161	-0.1099	0.3353	1.1762	0.72866	0.0343	0.0462	0.0547	0.010616
1e+12	0.0048	0.3926	0.9794	0.41589	0.0804	0.45015	1.0087	0.39623	0.0293	0.05755	0.0756	0.019803
5e+12	-0.5516	0.0522	0.3832	0.41357	-0.492	0.1071	0.4243	0.40867	0.0411	0.0549	0.0596	0.0092004
1e+13	-0.6404	0.35637	0.8923	0.67995	-0.6095	0.415	0.9587	0.69784	0.0309	0.058625	0.0801	0.020758

Device Test: 19.4 CURRENT|EA//4.5/4.5/0/0/4.5/500kHz//@EA_IB





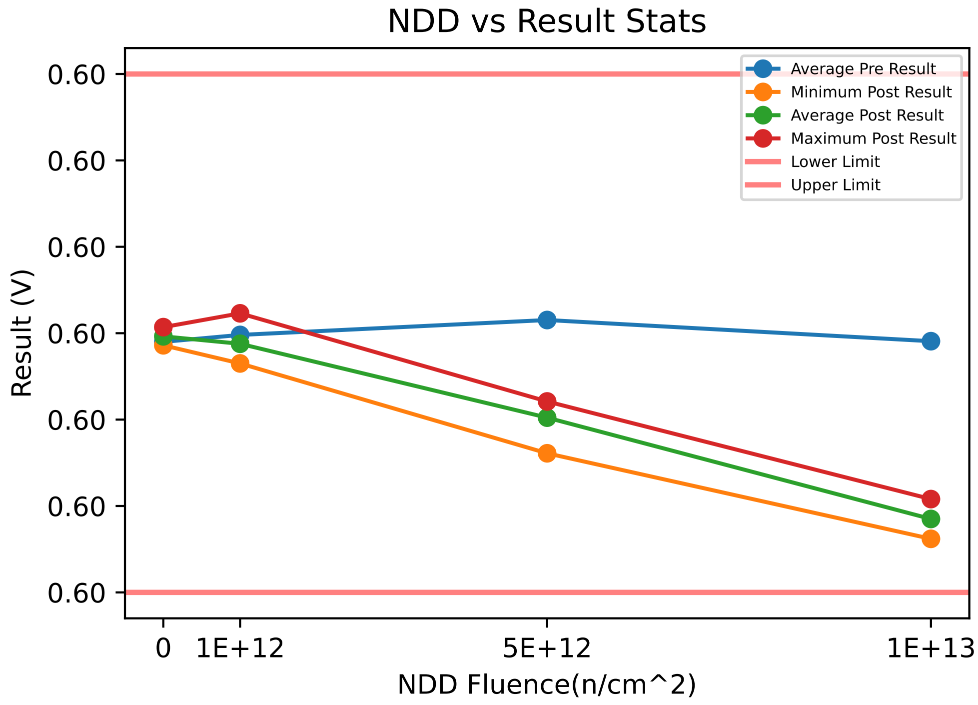
Test Results (Upper Limit = 25.0 (nA))

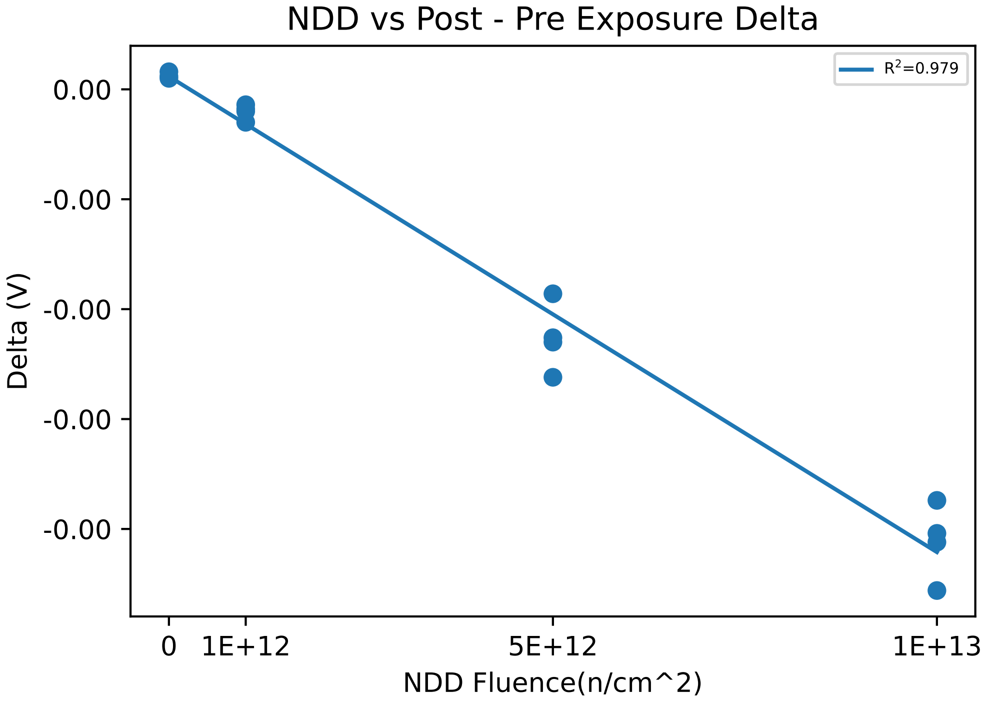
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.8432	0.3455	-0.4977
2	1e+12	NDD	-0.2356	0.4574	0.693
3	1e+12	NDD	-0.2644	1.2298	1.4942
4	1e+12	NDD	-0.0495	0.252	0.3015
5	5e+12	NDD	-0.4478	0.2045	0.6523
6	5e+12	NDD	-0.2114	1.0178	1.2292
7	5e+12	NDD	0.1284	0.2645	0.1361
8	5e+12	NDD	-0.3667	0.4074	0.7741
9	1e+13	NDD	-0.202	1.1114	1.3134
10	1e+13	NDD	0.0784	-0.2188	-0.2972
11	1e+13	NDD	-0.3323	-0.4043	-0.072
12	1e+13	NDD	-0.1333	0.9586	1.0919
13	0	CORRELATION	0.0972	-0.1128	-0.21
14	0	CORRELATION	-0.3199	-0.1577	0.1622
15	0	CORRELATION	-0.1802	1.0147	1.1949

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3199	-0.1343	0.0972	0.2123	-0.1577	0.24807	1.0147	0.6643	-0.21	0.38237	1.1949	0.72787
1e+12	-0.2644	0.073425	0.8432	0.52195	0.252	0.57117	1.2298	0.44704	-0.4977	0.49775	1.4942	0.82875
5e+12	-0.4478	-0.22437	0.1284	0.25482	0.2045	0.47355	1.0178	0.37268	0.1361	0.69793	1.2292	0.44936
1e+13	-0.3323	-0.1473	0.0784	0.17161	-0.4043	0.36172	1.1114	0.7836	-0.2972	0.50903	1.3134	0.81124

Device Test: 19.40 VOLTAGE|VREF//5/5/0/0/5/500kHz//@VREF_25C





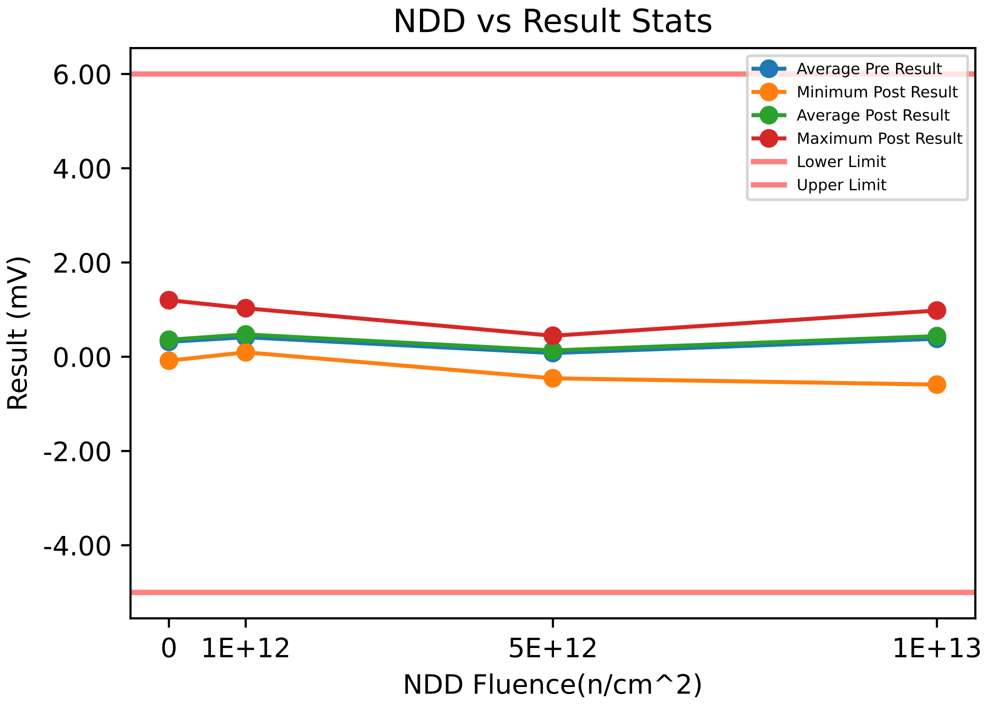
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

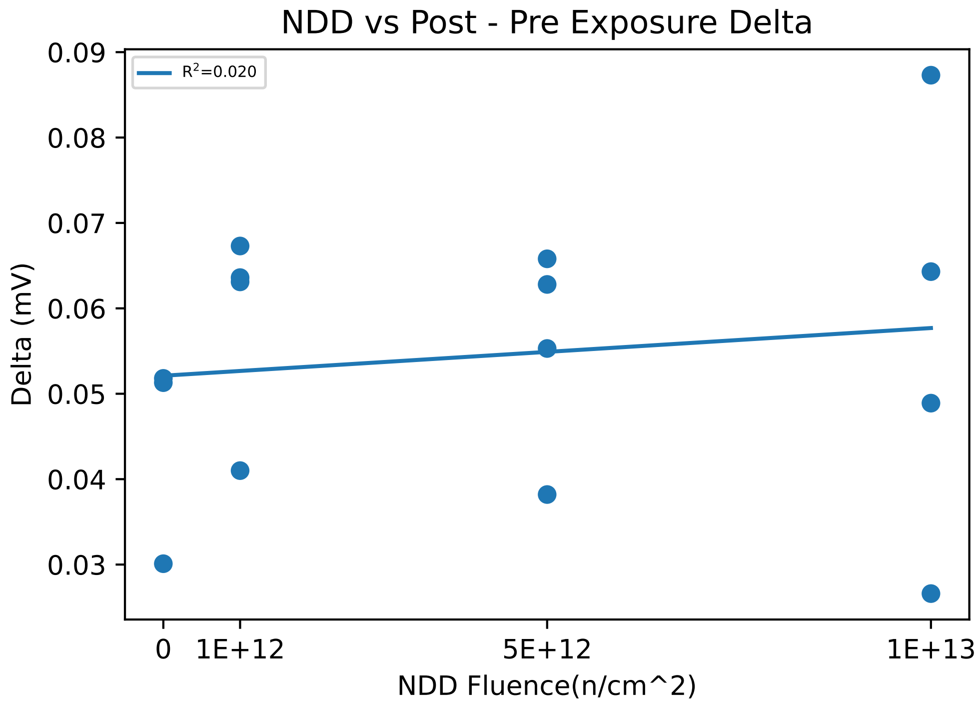
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59972	0.59965	-7e-05
2	1e+12	NDD	0.59995	0.59986	-9e-05
3	1e+12	NDD	0.59992	0.59977	-0.00015
4	1e+12	NDD	0.60033	0.60023	-0.0001
5	5e+12	NDD	0.60026	0.59911	-0.00115
6	5e+12	NDD	0.60029	0.59916	-0.00113
7	5e+12	NDD	0.60014	0.59921	-0.00093
8	5e+12	NDD	0.59992	0.59861	-0.00131
9	1e+13	NDD	0.59998	0.59792	-0.00206
10	1e+13	NDD	0.5998	0.59778	-0.00202
11	1e+13	NDD	0.59995	0.59808	-0.00187
12	1e+13	NDD	0.5999	0.59762	-0.00228
13	0	CORRELATION	0.5998	0.59986	6e-05
14	0	CORRELATION	0.59991	0.59996	5e-05
15	0	CORRELATION	0.59999	0.60007	8e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.59999	9.5394e-05	0.59986	0.59996	0.60007	0.00010504	5e-05	6.3333e-05	8e-05	1.5275e-05
1e+12	0.59972	0.59998	0.60033	0.00025469	0.59965	0.59988	0.60023	0.00025025	-0.00015	-0.0001025	-7e-05	3.4034e-05
5e+12	0.59992	0.60015	0.60029	0.000168	0.59861	0.59902	0.59921	0.00027801	-0.00131	-0.00113	-0.00093	0.00015578
1e+13	0.5998	0.59991	0.59998	7.8899e-05	0.59762	0.59785	0.59808	0.0001963	-0.00228	-0.0020575	-0.00187	0.00016939

Device Test: 19.42 VOLTAGE|OFFSET//5/5/0/0/5/500kHz//@EA_OS


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

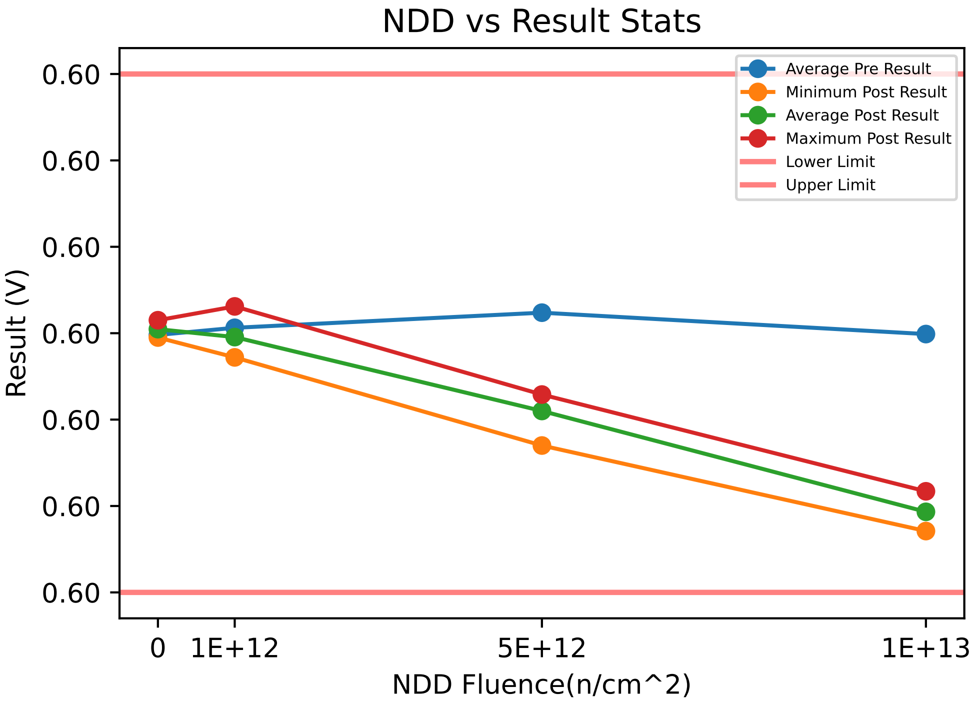
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

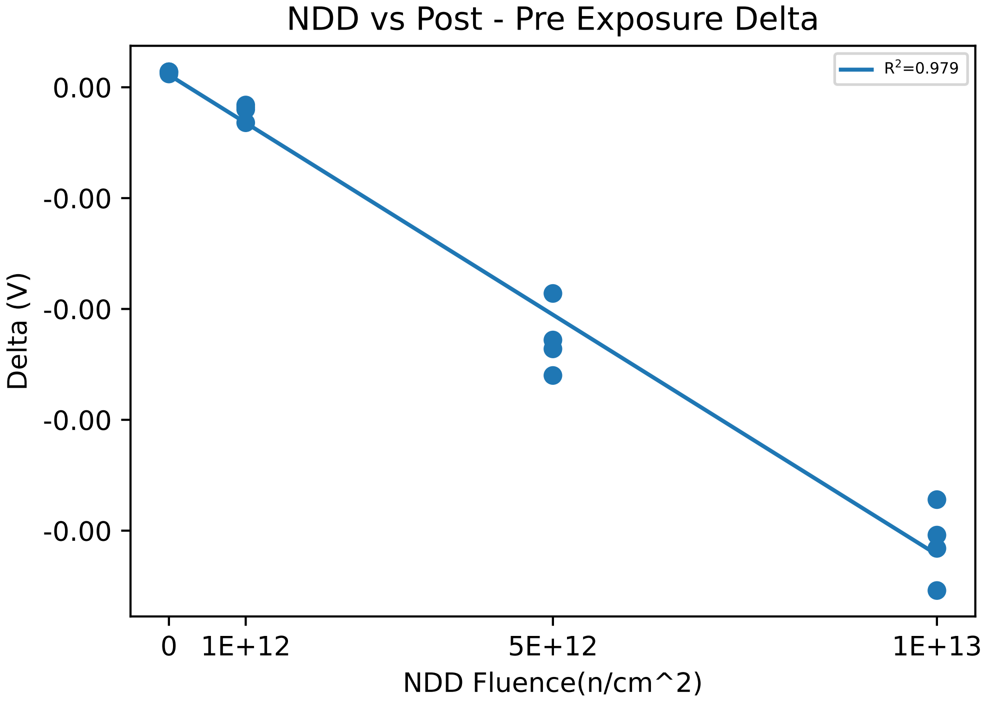
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3631	0.4304	0.0673
2	1e+12	NDD	0.2754	0.339	0.0636
3	1e+12	NDD	0.9893	1.0303	0.041
4	1e+12	NDD	0.031	0.0941	0.0631
5	5e+12	NDD	0.1855	0.2408	0.0553
6	5e+12	NDD	-0.5229	-0.4571	0.0658
7	5e+12	NDD	0.2445	0.3073	0.0628
8	5e+12	NDD	0.4079	0.4461	0.0382
9	1e+13	NDD	0.9169	0.9812	0.0643
10	1e+13	NDD	0.6053	0.6926	0.0873
11	1e+13	NDD	0.6203	0.6692	0.0489
12	1e+13	NDD	-0.6168	-0.5902	0.0266
13	0	CORRELATION	1.1489	1.2007	0.0518
14	0	CORRELATION	-0.0658	-0.0357	0.0301
15	0	CORRELATION	-0.1337	-0.0824	0.0513

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1337	0.31647	1.1489	0.72171	-0.0824	0.36087	1.2007	0.72769	0.0301	0.0444	0.0518	0.012387
1e+12	0.031	0.4147	0.9893	0.40803	0.0941	0.47345	1.0303	0.39746	0.041	0.05875	0.0673	0.011981
5e+12	-0.5229	0.07875	0.4079	0.41198	-0.4571	0.13428	0.4461	0.40342	0.0382	0.055525	0.0658	0.012365
1e+13	-0.6168	0.38143	0.9169	0.68078	-0.5902	0.4382	0.9812	0.70013	0.0266	0.056775	0.0873	0.025567

Device Test: 19.43 VOLTAGE|VREF//12/12/0/0/5/500kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

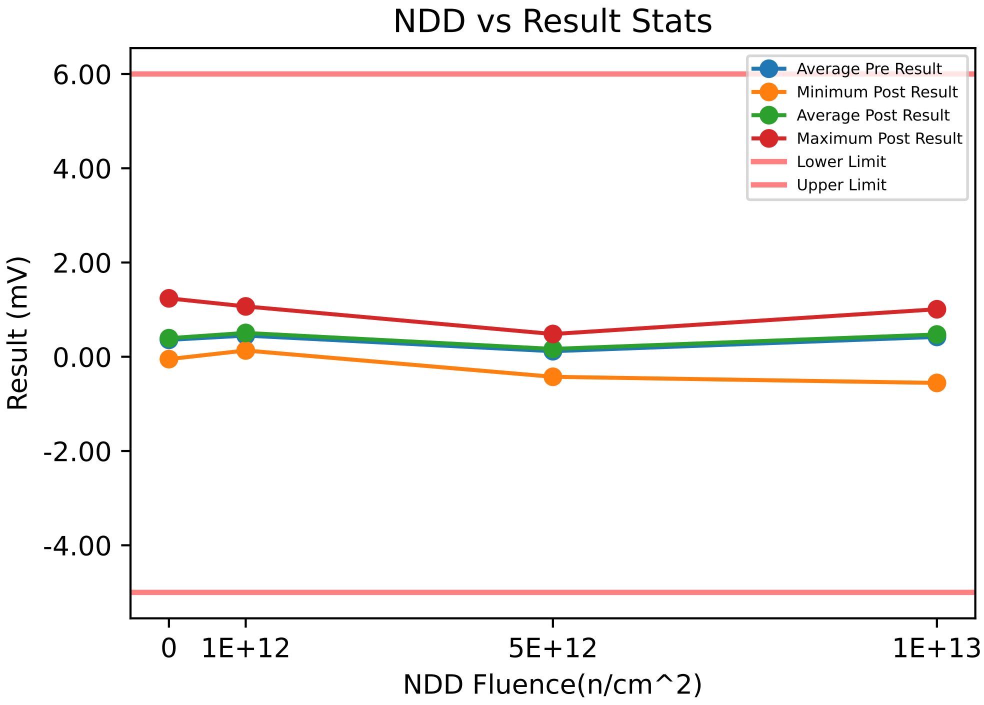
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

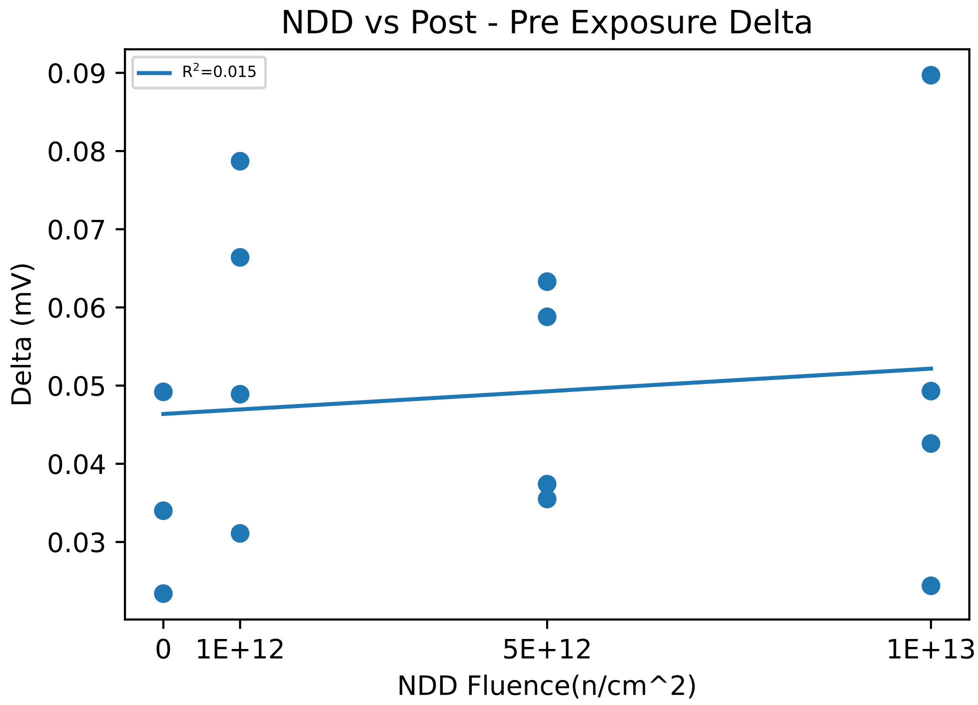
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5998	0.59972	-8e-05
2	1e+12	NDD	0.60003	0.59994	-9e-05
3	1e+12	NDD	0.60001	0.59985	-0.00016
4	1e+12	NDD	0.60041	0.60031	-0.0001
5	5e+12	NDD	0.60035	0.59917	-0.00118
6	5e+12	NDD	0.60038	0.59924	-0.00114
7	5e+12	NDD	0.60022	0.59929	-0.00093
8	5e+12	NDD	0.6	0.5987	-0.0013
9	1e+13	NDD	0.60007	0.59799	-0.00208
10	1e+13	NDD	0.59988	0.59786	-0.00202
11	1e+13	NDD	0.60003	0.59817	-0.00186
12	1e+13	NDD	0.59998	0.59771	-0.00227
13	0	CORRELATION	0.59988	0.59995	7e-05
14	0	CORRELATION	0.59998	0.60004	6e-05
15	0	CORRELATION	0.60008	0.60015	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59988	0.59998	0.60008	0.0001	0.59995	0.60005	0.60015	0.00010017	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.5998	0.60006	0.60041	0.00025395	0.59972	0.59996	0.60031	0.00025331	-0.00016	-0.0001075	-8e-05	3.594e-05
5e+12	0.6	0.60024	0.60038	0.00017289	0.5987	0.5991	0.59929	0.00027117	-0.0013	-0.0011375	-0.00093	0.00015414
1e+13	0.59988	0.59999	0.60007	8.2057e-05	0.59771	0.59793	0.59817	0.00019534	-0.00227	-0.0020575	-0.00186	0.00016939

Device Test: 19.45 VOLTAGE|OFFSET//12/12/0/0/5/500kHz//@EA_OS





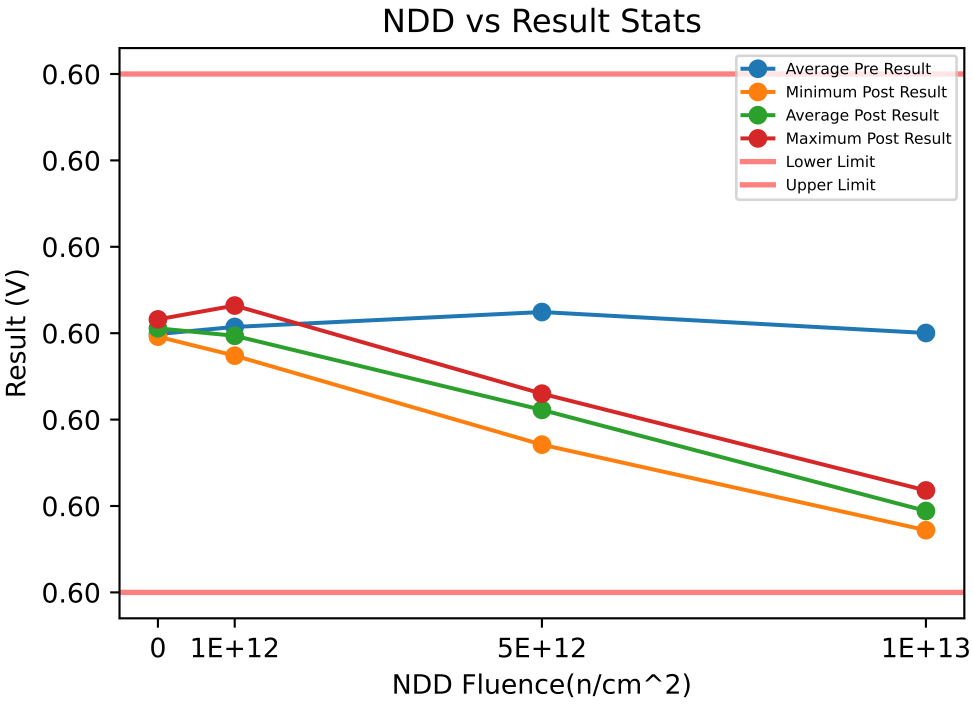
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

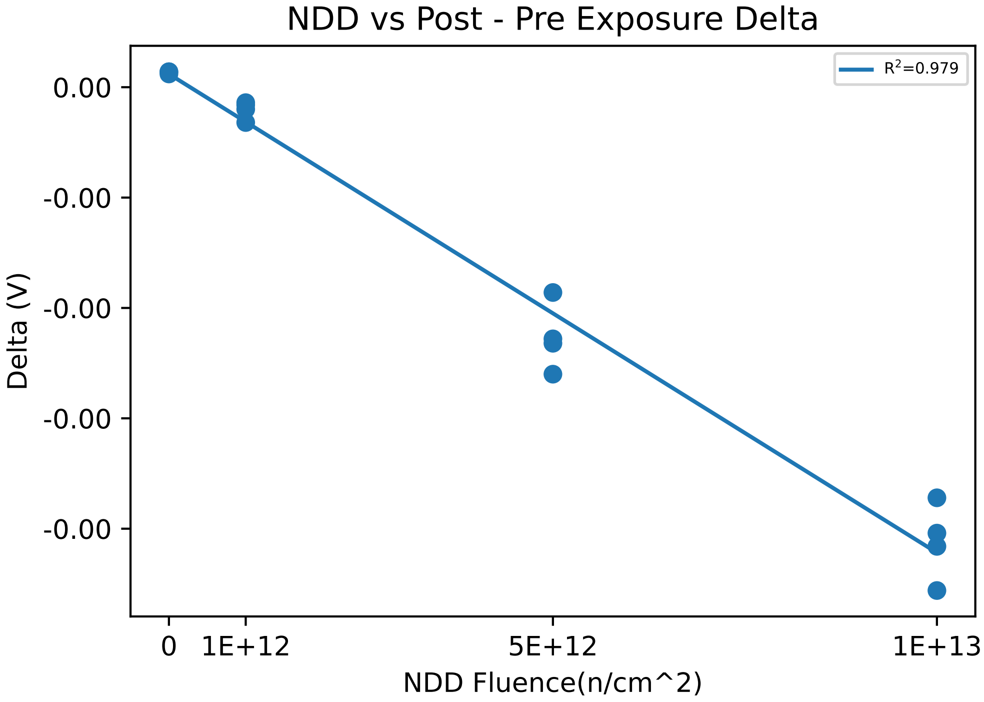
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3987	0.4476	0.0489
2	1e+12	NDD	0.307	0.3734	0.0664
3	1e+12	NDD	1.0373	1.0684	0.0311
4	1e+12	NDD	0.0545	0.1332	0.0787
5	5e+12	NDD	0.2276	0.265	0.0374
6	5e+12	NDD	-0.484	-0.4252	0.0588
7	5e+12	NDD	0.2807	0.344	0.0633
8	5e+12	NDD	0.4471	0.4826	0.0355
9	1e+13	NDD	0.9655	1.0081	0.0426
10	1e+13	NDD	0.6407	0.7304	0.0897
11	1e+13	NDD	0.6584	0.7077	0.0493
12	1e+13	NDD	-0.5798	-0.5554	0.0244
13	0	CORRELATION	1.1904	1.2396	0.0492
14	0	CORRELATION	-0.0303	-0.0069	0.0234
15	0	CORRELATION	-0.0842	-0.0502	0.034

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0842	0.35863	1.1904	0.72084	-0.0502	0.39417	1.2396	0.73249	0.0234	0.035533	0.0492	0.012968
1e+12	0.0545	0.44938	1.0373	0.4181	0.1332	0.50565	1.0684	0.39844	0.0311	0.056275	0.0787	0.020765
5e+12	-0.484	0.11785	0.4471	0.41198	-0.4252	0.1666	0.4826	0.40465	0.0355	0.04875	0.0633	0.014342
1e+13	-0.5798	0.4212	0.9655	0.68379	-0.5554	0.4727	1.0081	0.69887	0.0244	0.0515	0.0897	0.027554

Device Test: 19.46 VOLTAGE|VREF//14/14/0/0/5/500kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

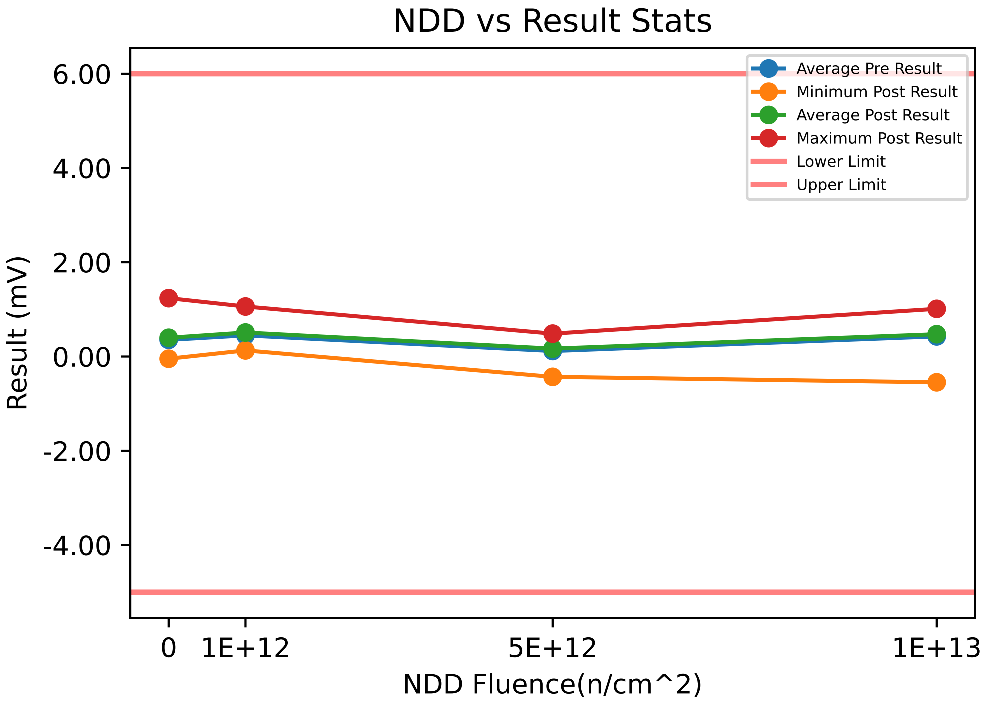
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

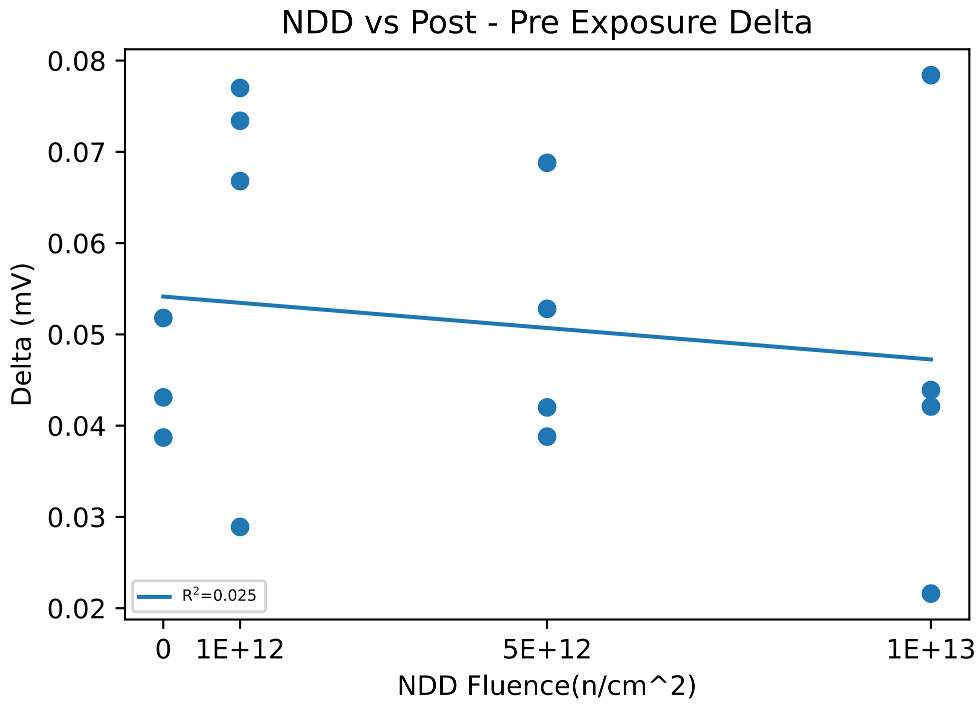
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59981	0.59974	-7e-05
2	1e+12	NDD	0.60004	0.59996	-8e-05
3	1e+12	NDD	0.60002	0.59986	-0.00016
4	1e+12	NDD	0.60042	0.60032	-0.0001
5	5e+12	NDD	0.60035	0.59919	-0.00116
6	5e+12	NDD	0.60039	0.59925	-0.00114
7	5e+12	NDD	0.60023	0.5993	-0.00093
8	5e+12	NDD	0.60001	0.59871	-0.0013
9	1e+13	NDD	0.60008	0.598	-0.00208
10	1e+13	NDD	0.59989	0.59787	-0.00202
11	1e+13	NDD	0.60004	0.59818	-0.00186
12	1e+13	NDD	0.6	0.59772	-0.00228
13	0	CORRELATION	0.59989	0.59996	7e-05
14	0	CORRELATION	0.59999	0.60005	6e-05
15	0	CORRELATION	0.60009	0.60016	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59989	0.59999	0.60009	0.0001	0.59996	0.60006	0.60016	0.00010017	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.59981	0.60007	0.60042	0.00025395	0.59974	0.59997	0.60032	0.00025007	-0.00016	-0.0001025	-7e-05	4.0311e-05
5e+12	0.60001	0.60025	0.60039	0.00017078	0.59871	0.59911	0.5993	0.00027208	-0.0013	-0.0011325	-0.00093	0.00015262
1e+13	0.59989	0.6	0.60008	8.1803e-05	0.59772	0.59794	0.59818	0.00019534	-0.00228	-0.00206	-0.00186	0.00017359

Device Test: 19.48 VOLTAGE|OFFSET//14/14/0/0/5/500kHz//@EA_OS





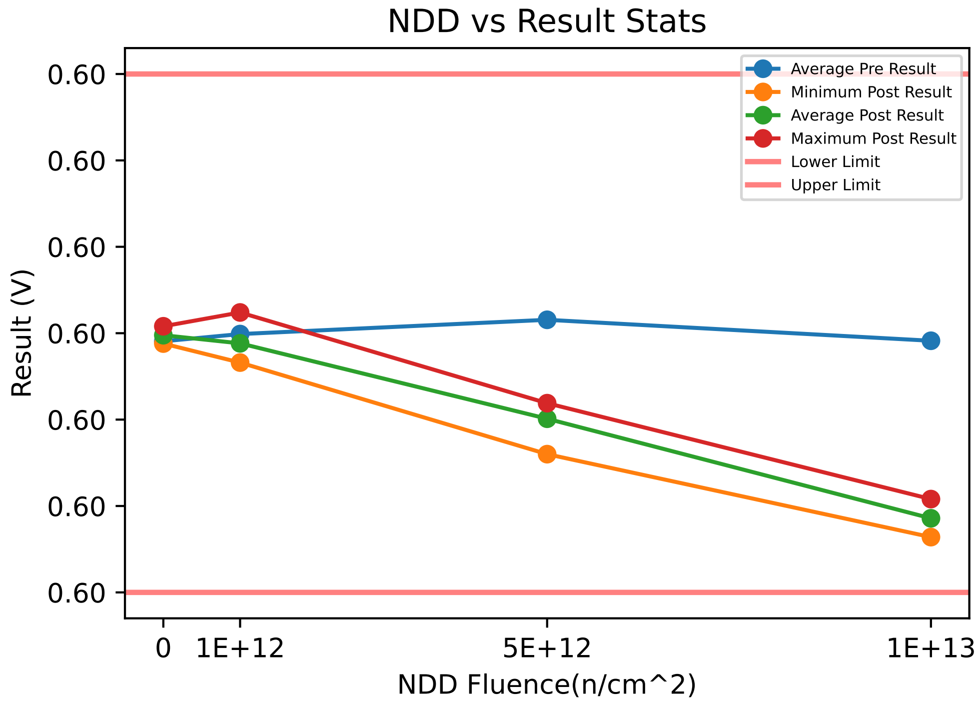
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

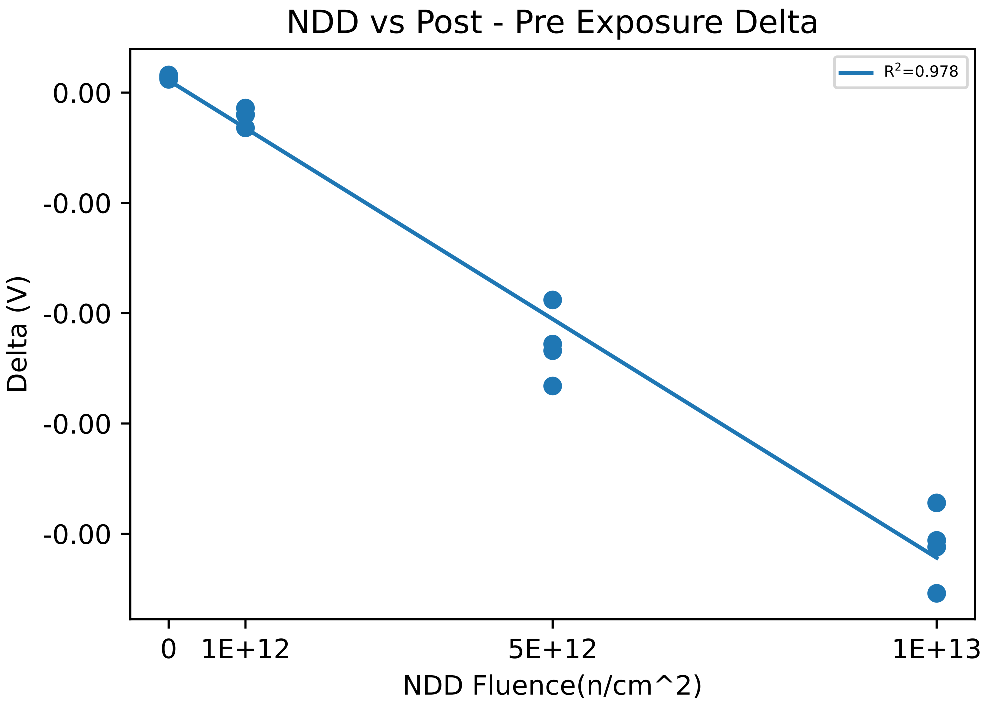
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3975	0.4643	0.0668
2	1e+12	NDD	0.3054	0.3824	0.077
3	1e+12	NDD	1.0325	1.0614	0.0289
4	1e+12	NDD	0.0562	0.1296	0.0734
5	5e+12	NDD	0.2148	0.2676	0.0528
6	5e+12	NDD	-0.4734	-0.4314	0.042
7	5e+12	NDD	0.2793	0.3481	0.0688
8	5e+12	NDD	0.4469	0.4857	0.0388
9	1e+13	NDD	0.9699	1.012	0.0421
10	1e+13	NDD	0.6408	0.7192	0.0784
11	1e+13	NDD	0.6665	0.7104	0.0439
12	1e+13	NDD	-0.5689	-0.5473	0.0216
13	0	CORRELATION	1.1867	1.2385	0.0518
14	0	CORRELATION	-0.0366	0.0021	0.0387
15	0	CORRELATION	-0.0897	-0.0466	0.0431

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0897	0.35347	1.1867	0.72209	-0.0466	0.398	1.2385	0.7283	0.0387	0.044533	0.0518	0.0066666
1e+12	0.0562	0.4479	1.0325	0.41554	0.1296	0.50943	1.0614	0.39459	0.0289	0.061525	0.077	0.022156
5e+12	-0.4734	0.1169	0.4469	0.40551	-0.4314	0.1675	0.4857	0.4093	0.0388	0.0506	0.0688	0.013531
1e+13	-0.5689	0.42707	0.9699	0.68059	-0.5473	0.47357	1.012	0.69486	0.0216	0.0465	0.0784	0.02355

Device Test: 19.49 VOLTAGE|VREF//4.5/4.5/0/0/4.5/1MHz//@VREF_25C





Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

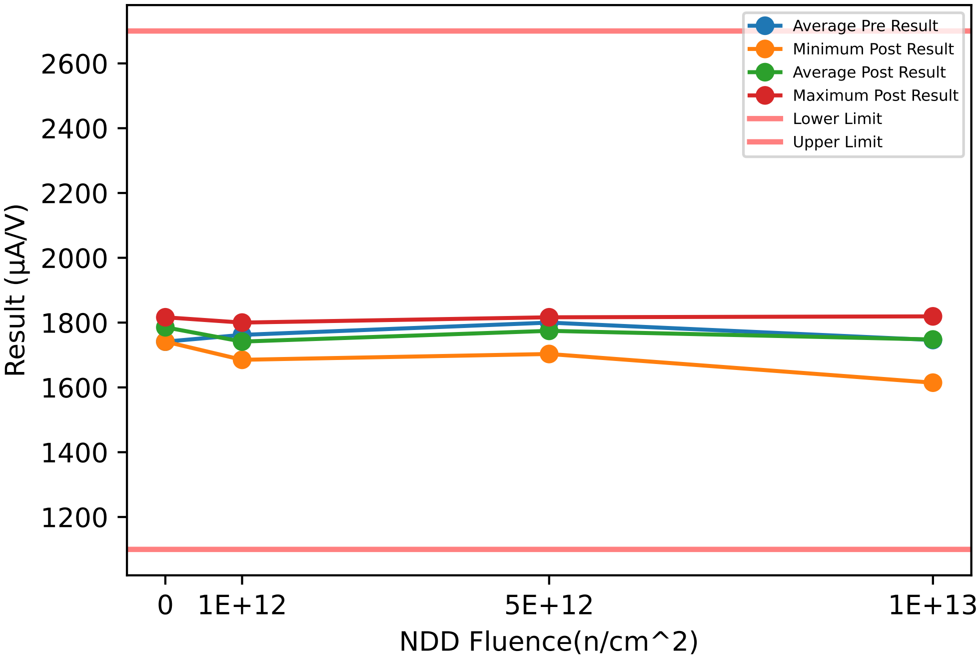
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59973	0.59966	-7e-05
2	1e+12	NDD	0.59996	0.59986	-0.0001
3	1e+12	NDD	0.59993	0.59977	-0.00016
4	1e+12	NDD	0.60034	0.60024	-0.0001
5	5e+12	NDD	0.60026	0.59909	-0.00117
6	5e+12	NDD	0.6003	0.59916	-0.00114
7	5e+12	NDD	0.60013	0.59919	-0.00094
8	5e+12	NDD	0.59993	0.5986	-0.00133
9	1e+13	NDD	0.59999	0.59793	-0.00206
10	1e+13	NDD	0.59981	0.59778	-0.00203
11	1e+13	NDD	0.59994	0.59808	-0.00186
12	1e+13	NDD	0.59991	0.59764	-0.00227
13	0	CORRELATION	0.5998	0.59988	8e-05
14	0	CORRELATION	0.59991	0.59997	6e-05
15	0	CORRELATION	0.60001	0.60008	7e-05

Test Statistics (V)

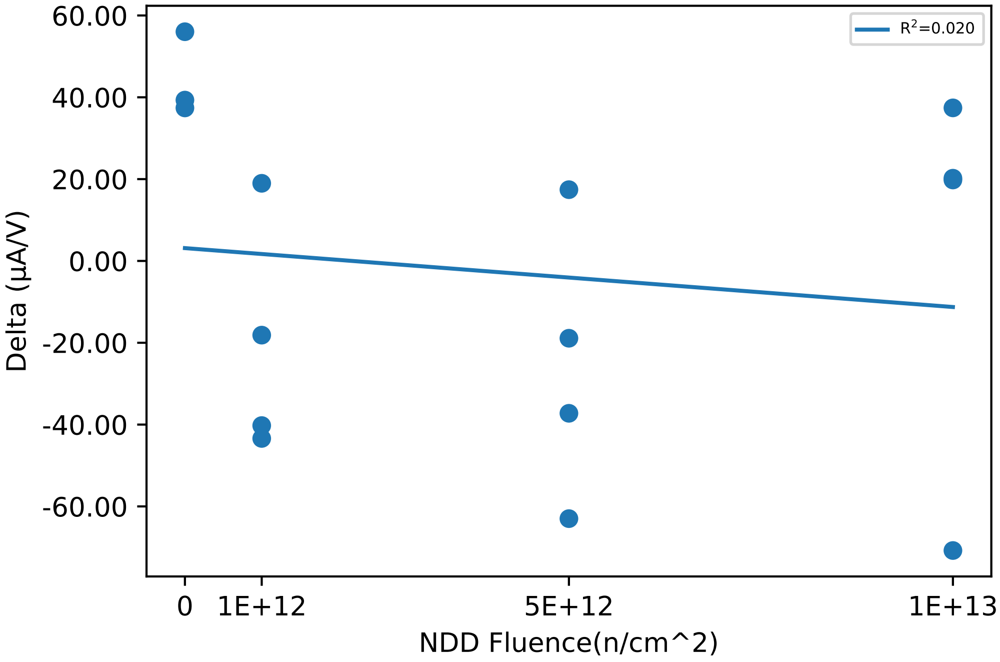
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59991	0.60001	0.00010504	0.59988	0.59998	0.60008	0.00010017	6e-05	7e-05	8e-05	1e-05
1e+12	0.59973	0.59999	0.60034	0.00025469	0.59966	0.59988	0.60024	0.00025198	-0.00016	-0.0001075	-7e-05	3.7749e-05
5e+12	0.59993	0.60015	0.6003	0.00016663	0.5986	0.59901	0.59919	0.00027653	-0.00133	-0.001145	-0.00094	0.0001601
1e+13	0.59981	0.59991	0.59999	7.5884e-05	0.59764	0.59786	0.59808	0.0001898	-0.00227	-0.002055	-0.00186	0.00016823

Device Test: 19.5 LEVEL|TRANSCONDUCTANCE//5/5/0/0/5/500kHz//@EA_GM

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



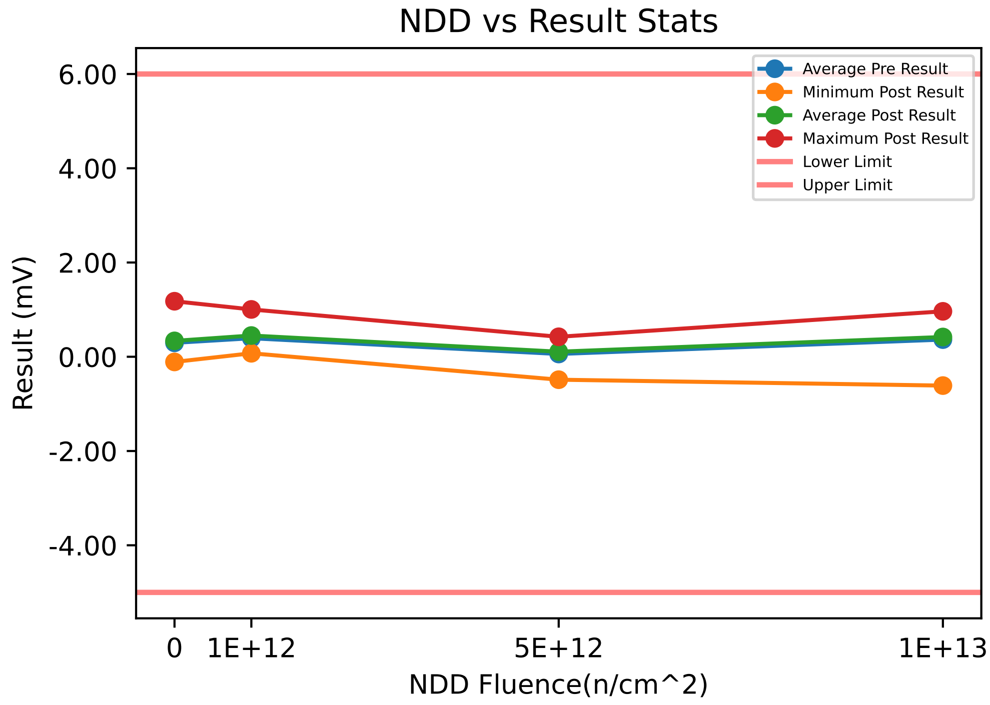
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

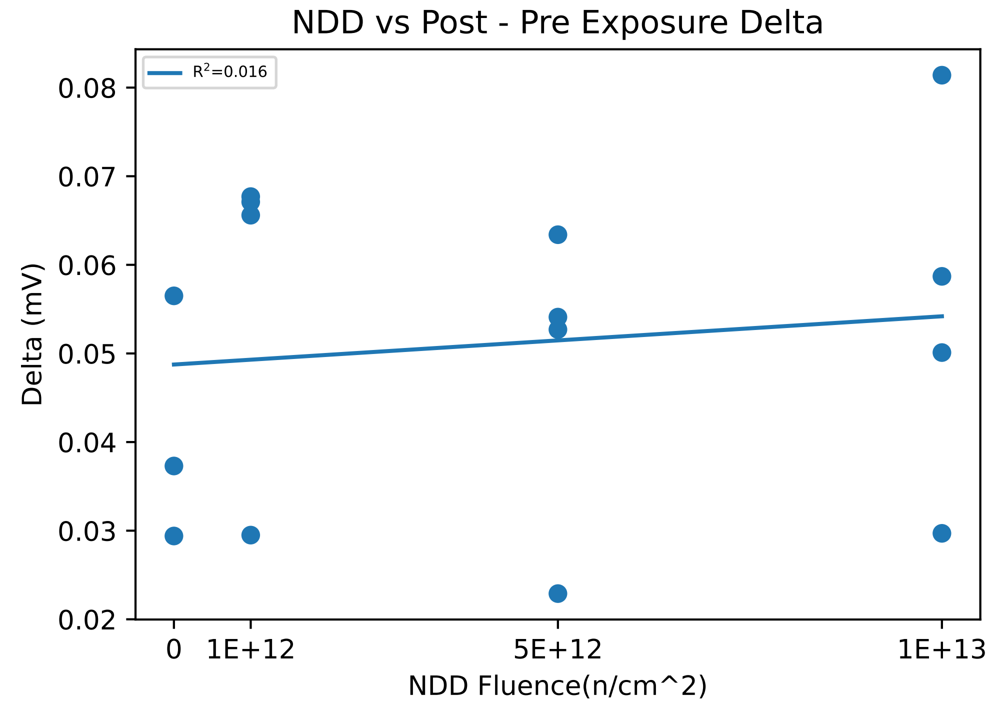
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1840.3	1800	-40.239
2	1e+12	NDD	1703.3	1685.2	-18.136
3	1e+12	NDD	1819.4	1776	-43.384
4	1e+12	NDD	1685.3	1704.3	18.977
5	5e+12	NDD	1861.8	1798.8	-62.987
6	5e+12	NDD	1799	1816.4	17.422
7	5e+12	NDD	1798.9	1780	-18.895
8	5e+12	NDD	1740.4	1703.1	-37.242
9	1e+13	NDD	1685.3	1614.6	-70.78
10	1e+13	NDD	1721.5	1741.3	19.789
11	1e+13	NDD	1799	1819.2	20.22
12	1e+13	NDD	1779	1816.4	37.413
13	0	CORRELATION	1685.3	1741.3	56.027
14	0	CORRELATION	1759.5	1798.8	39.313
15	0	CORRELATION	1779	1816.4	37.403

Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1685.3	1741.3	1779	49.425	1741.3	1785.5	1816.4	39.251	37.403	44.248	56.027	10.246
1e+12	1685.3	1762.1	1840.3	79.057	1685.2	1741.4	1800	55.306	-43.384	-20.695	18.977	28.736
5e+12	1740.4	1800	1861.8	49.58	1703.1	1774.6	1816.4	49.903	-62.987	-25.426	17.422	33.808
1e+13	1685.3	1746.2	1799	52.203	1614.6	1747.9	1819.2	95.919	-70.78	1.6604	37.413	48.986

Device Test: 19.51 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/1MHz//@EA_OS


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

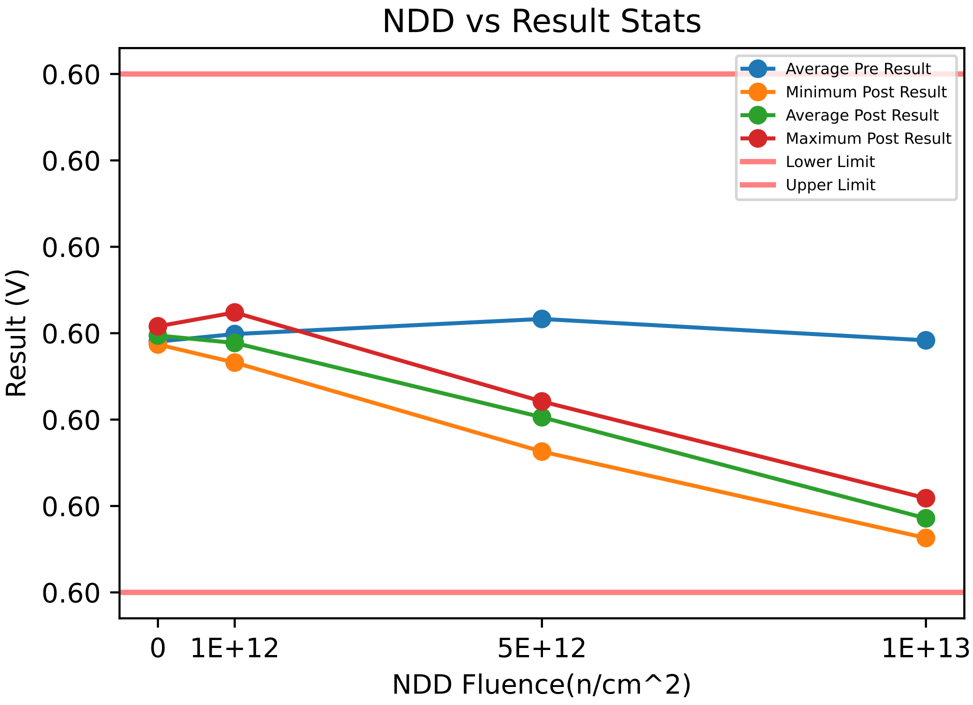
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

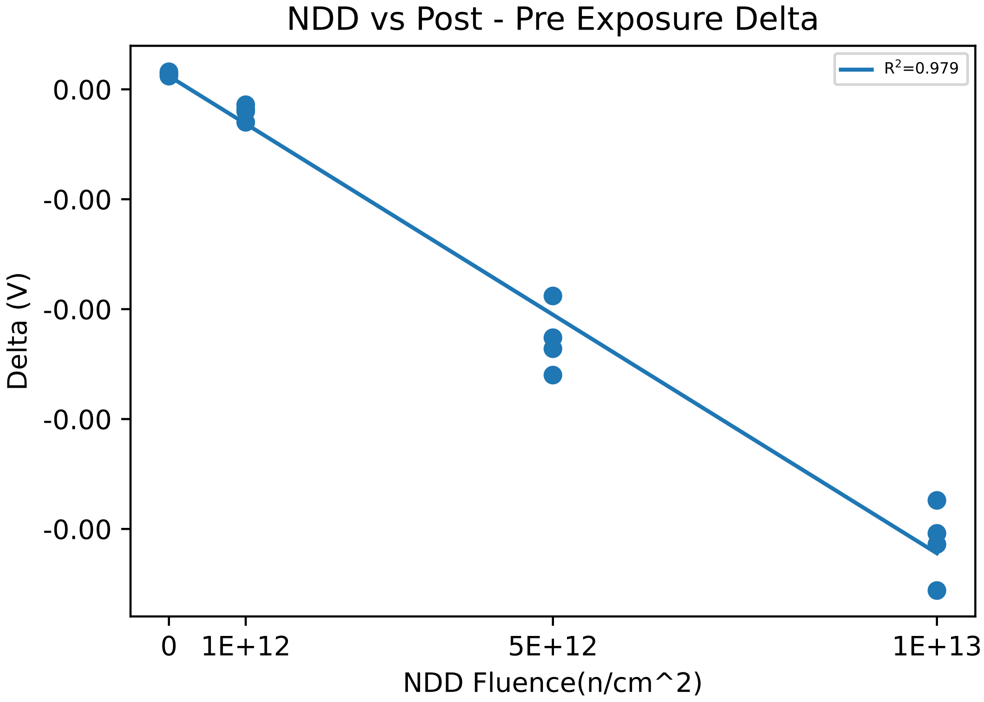
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3426	0.4082	0.0656
2	1e+12	NDD	0.2483	0.3154	0.0671
3	1e+12	NDD	0.975	1.0045	0.0295
4	1e+12	NDD	0.0062	0.0739	0.0677
5	5e+12	NDD	0.1573	0.2114	0.0541
6	5e+12	NDD	-0.5394	-0.4867	0.0527
7	5e+12	NDD	0.2178	0.2812	0.0634
8	5e+12	NDD	0.4008	0.4237	0.0229
9	1e+13	NDD	0.905	0.9637	0.0587
10	1e+13	NDD	0.5912	0.6726	0.0814
11	1e+13	NDD	0.6022	0.6523	0.0501
12	1e+13	NDD	-0.6412	-0.6115	0.0297
13	0	CORRELATION	1.1215	1.178	0.0565
14	0	CORRELATION	-0.0878	-0.0584	0.0294
15	0	CORRELATION	-0.1467	-0.1094	0.0373

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1467	0.29567	1.1215	0.7158	-0.1094	0.33673	1.178	0.729	0.0294	0.041067	0.0565	0.013937
1e+12	0.0062	0.39303	0.975	0.41304	0.0739	0.4505	1.0045	0.3953	0.0295	0.057475	0.0677	0.018671
5e+12	-0.5394	0.059125	0.4008	0.41223	-0.4867	0.1074	0.4237	0.4058	0.0229	0.048275	0.0634	0.017571
1e+13	-0.6412	0.3643	0.905	0.68592	-0.6115	0.41927	0.9637	0.70175	0.0297	0.054975	0.0814	0.021407

Device Test: 19.52 VOLTAGE|VREF//5/5/0/0/5/1MHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

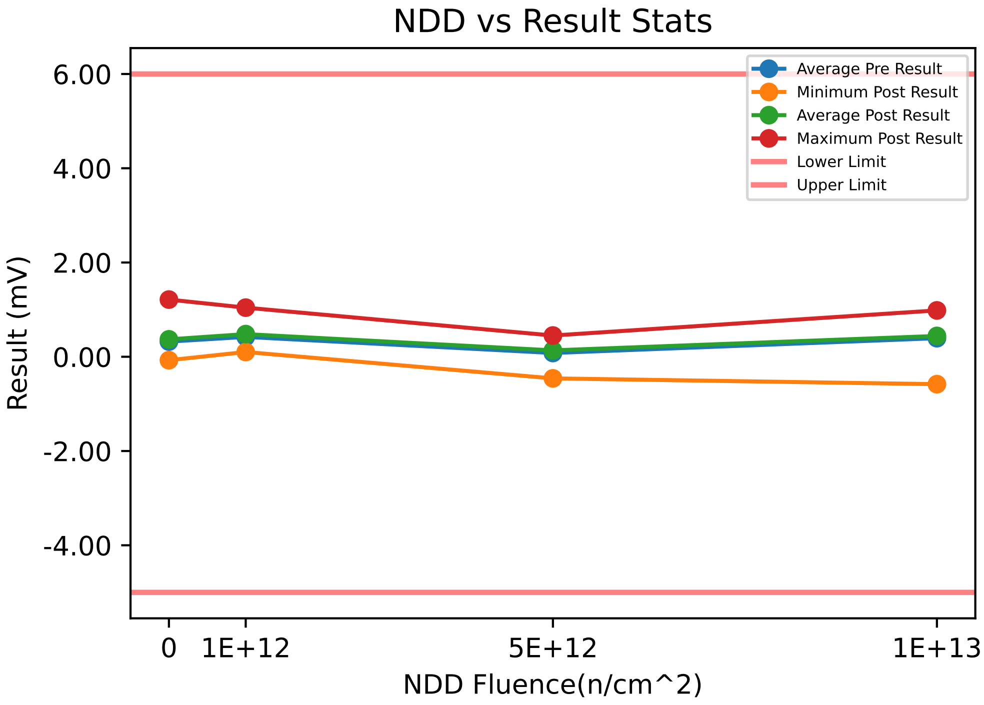
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

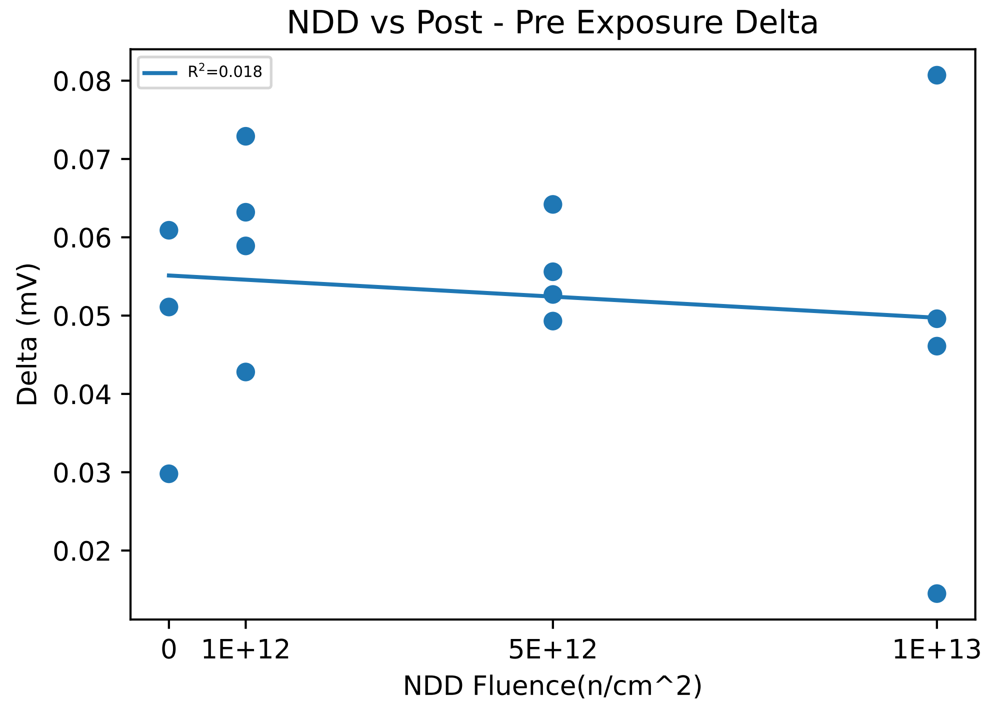
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59973	0.59966	-7e-05
2	1e+12	NDD	0.59996	0.59987	-9e-05
3	1e+12	NDD	0.59993	0.59978	-0.00015
4	1e+12	NDD	0.60034	0.60024	-0.0001
5	5e+12	NDD	0.60028	0.5991	-0.00118
6	5e+12	NDD	0.6003	0.59917	-0.00113
7	5e+12	NDD	0.60015	0.59921	-0.00094
8	5e+12	NDD	0.59993	0.59863	-0.0013
9	1e+13	NDD	0.59999	0.59792	-0.00207
10	1e+13	NDD	0.59981	0.59779	-0.00202
11	1e+13	NDD	0.59996	0.59809	-0.00187
12	1e+13	NDD	0.59991	0.59763	-0.00228
13	0	CORRELATION	0.5998	0.59987	7e-05
14	0	CORRELATION	0.59991	0.59997	6e-05
15	0	CORRELATION	0.6	0.60008	8e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.6	0.00010017	0.59987	0.59997	0.60008	0.00010504	6e-05	7e-05	8e-05	1e-05
1e+12	0.59973	0.59999	0.60034	0.00025469	0.59966	0.59989	0.60024	0.00025025	-0.00015	-0.0001025	-7e-05	3.4034e-05
5e+12	0.59993	0.60016	0.6003	0.0001702	0.59863	0.59903	0.59921	0.00026887	-0.0013	-0.0011375	-0.00094	0.00014975
1e+13	0.59981	0.59992	0.59999	7.8899e-05	0.59763	0.59786	0.59809	0.00019517	-0.00228	-0.00206	-0.00187	0.00016951

Device Test: 19.54 VOLTAGE|OFFSET//5/5/0/0/5/1MHz//@EA_OS





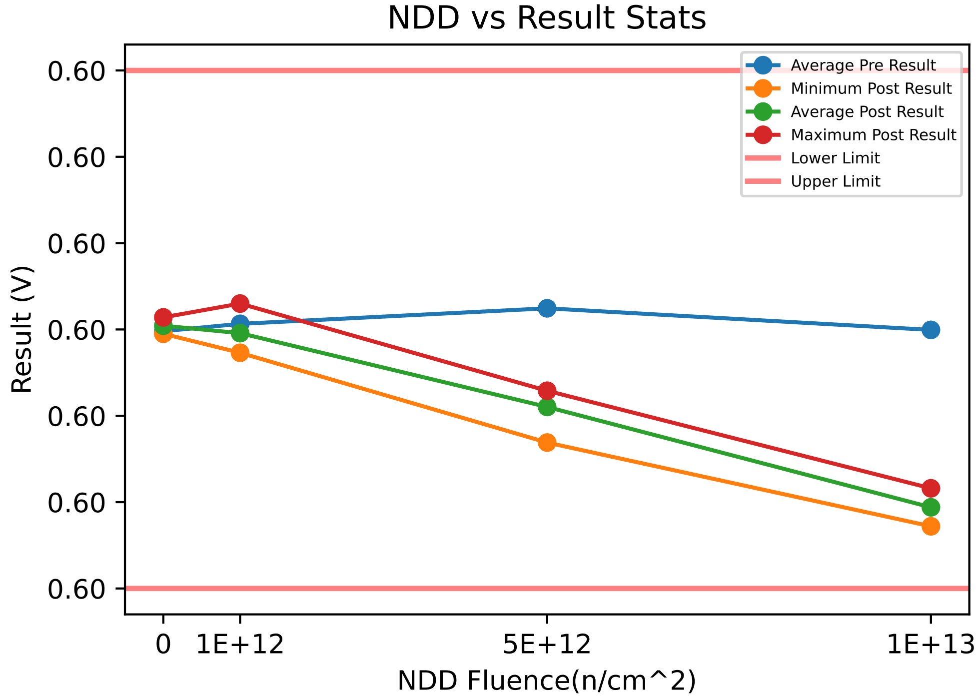
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

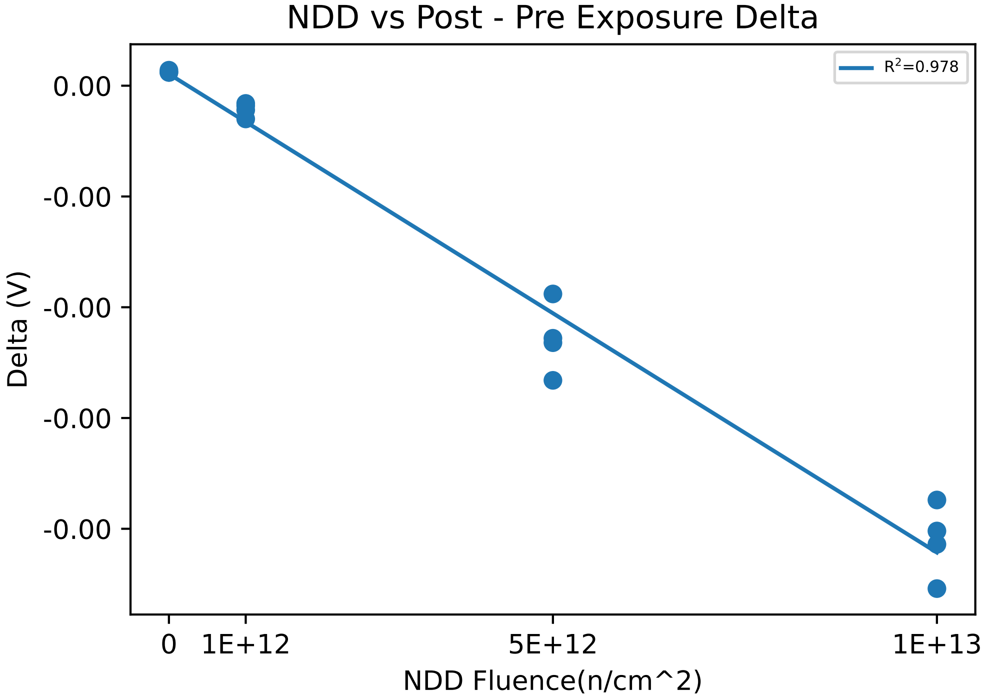
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.3723	0.4312	0.0589
2	1e+12	NDD	0.2851	0.3483	0.0632
3	1e+12	NDD	0.9993	1.0421	0.0428
4	1e+12	NDD	0.0279	0.1008	0.0729
5	5e+12	NDD	0.1878	0.2405	0.0527
6	5e+12	NDD	-0.5142	-0.4586	0.0556
7	5e+12	NDD	0.2455	0.3097	0.0642
8	5e+12	NDD	0.4015	0.4508	0.0493
9	1e+13	NDD	0.9338	0.9834	0.0496
10	1e+13	NDD	0.6096	0.6903	0.0807
11	1e+13	NDD	0.6286	0.6747	0.0461
12	1e+13	NDD	-0.5962	-0.5817	0.0145
13	0	CORRELATION	1.1524	1.2133	0.0609
14	0	CORRELATION	-0.062	-0.0322	0.0298
15	0	CORRELATION	-0.1241	-0.073	0.0511

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1241	0.3221	1.1524	0.71973	-0.073	0.36937	1.2133	0.73115	0.0298	0.047267	0.0609	0.0159
1e+12	0.0279	0.42115	0.9993	0.41223	0.1008	0.4806	1.0421	0.39978	0.0428	0.05945	0.0729	0.01255
5e+12	-0.5142	0.08015	0.4015	0.40639	-0.4586	0.1356	0.4508	0.40568	0.0493	0.05545	0.0642	0.0063763
1e+13	-0.5962	0.39395	0.9338	0.67661	-0.5817	0.44168	0.9834	0.69687	0.0145	0.047725	0.0807	0.027064

Device Test: 19.55 VOLTAGE|VREF//12/12/0/0/5/1MHz//@VREF_25C





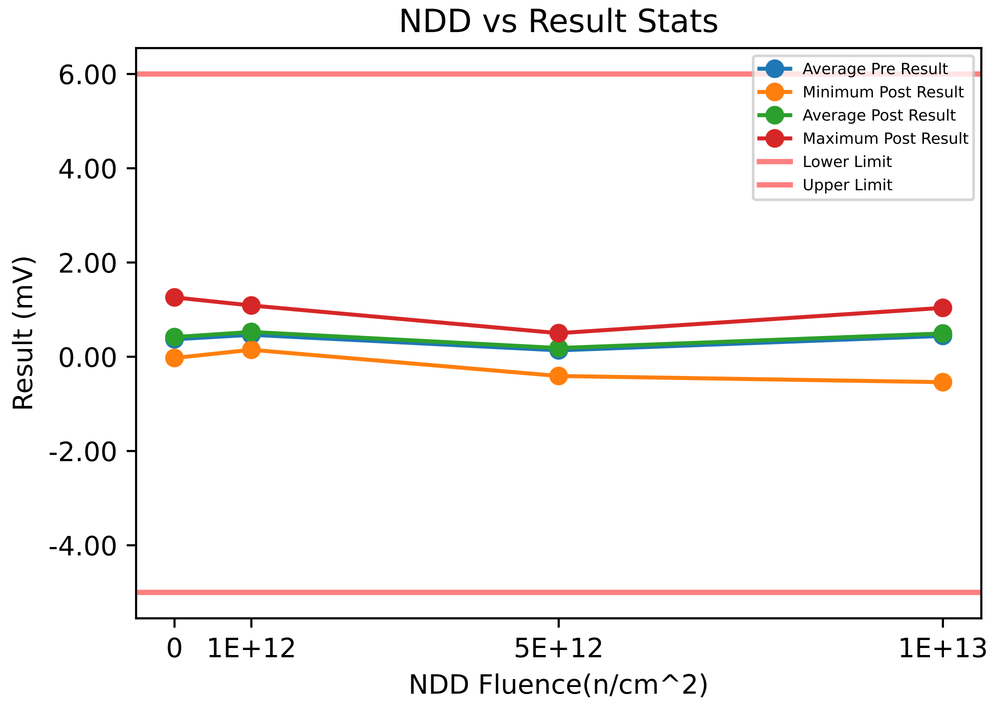
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

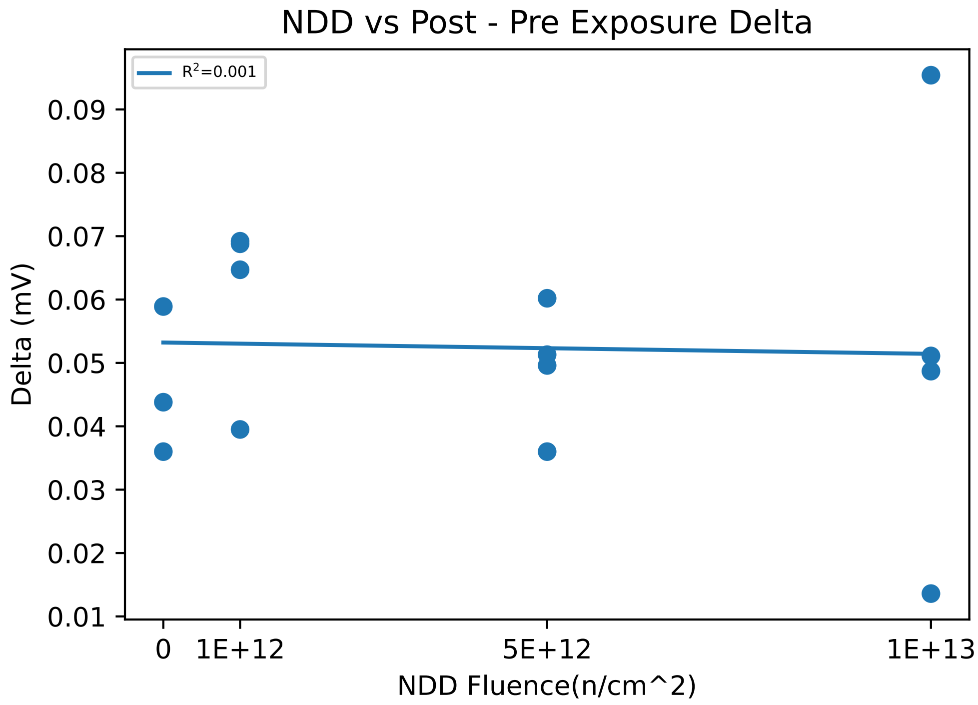
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59981	0.59973	-8e-05
2	1e+12	NDD	0.60003	0.59994	-9e-05
3	1e+12	NDD	0.60001	0.59986	-0.00015
4	1e+12	NDD	0.60041	0.6003	-0.00011
5	5e+12	NDD	0.60035	0.59919	-0.00116
6	5e+12	NDD	0.60038	0.59924	-0.00114
7	5e+12	NDD	0.60023	0.59929	-0.00094
8	5e+12	NDD	0.60002	0.59869	-0.00133
9	1e+13	NDD	0.60008	0.59801	-0.00207
10	1e+13	NDD	0.59988	0.59787	-0.00201
11	1e+13	NDD	0.60003	0.59816	-0.00187
12	1e+13	NDD	0.59999	0.59772	-0.00227
13	0	CORRELATION	0.59988	0.59995	7e-05
14	0	CORRELATION	0.59998	0.60004	6e-05
15	0	CORRELATION	0.60008	0.60014	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59988	0.59998	0.60008	0.0001	0.59995	0.60004	0.60014	9.5044e-05	6e-05	6.3333e-05	7e-05	5.7735e-06
1e+12	0.59981	0.60006	0.60041	0.00025053	0.59973	0.59996	0.6003	0.00024418	-0.00015	-0.0001075	-8e-05	3.0957e-05
5e+12	0.60002	0.60025	0.60038	0.0001634	0.59869	0.5991	0.59929	0.00027801	-0.00133	-0.0011425	-0.00094	0.00015966
1e+13	0.59988	0.59999	0.60008	8.5049e-05	0.59772	0.59794	0.59816	0.0001885	-0.00227	-0.002055	-0.00187	0.00016603

Device Test: 19.57 VOLTAGE|OFFSET//12/12/0/0/5/1MHz//@EA_OS


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

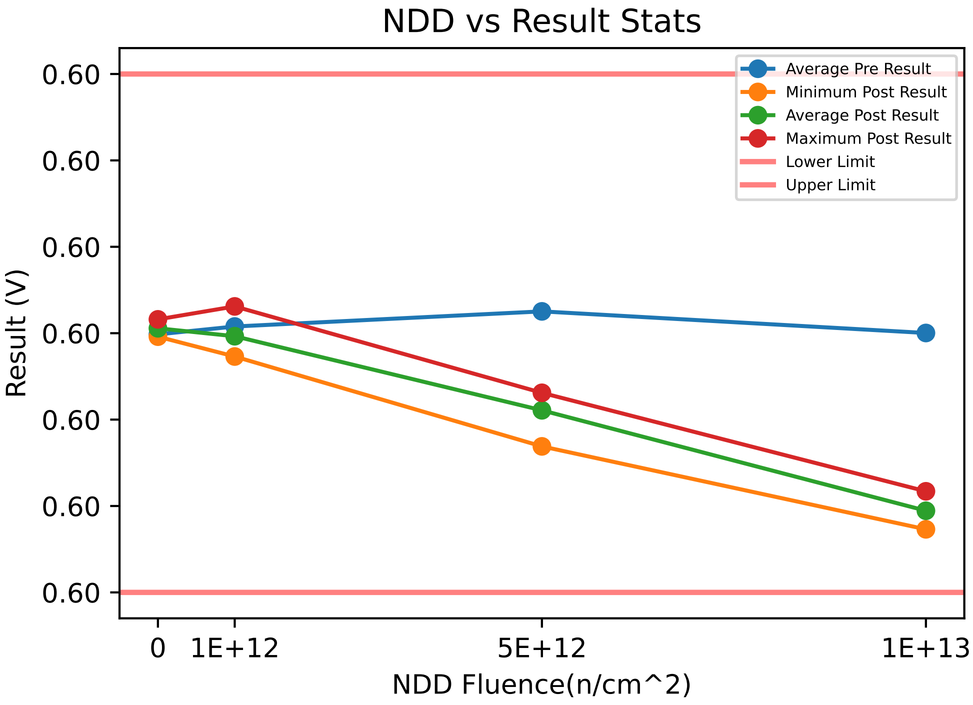
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

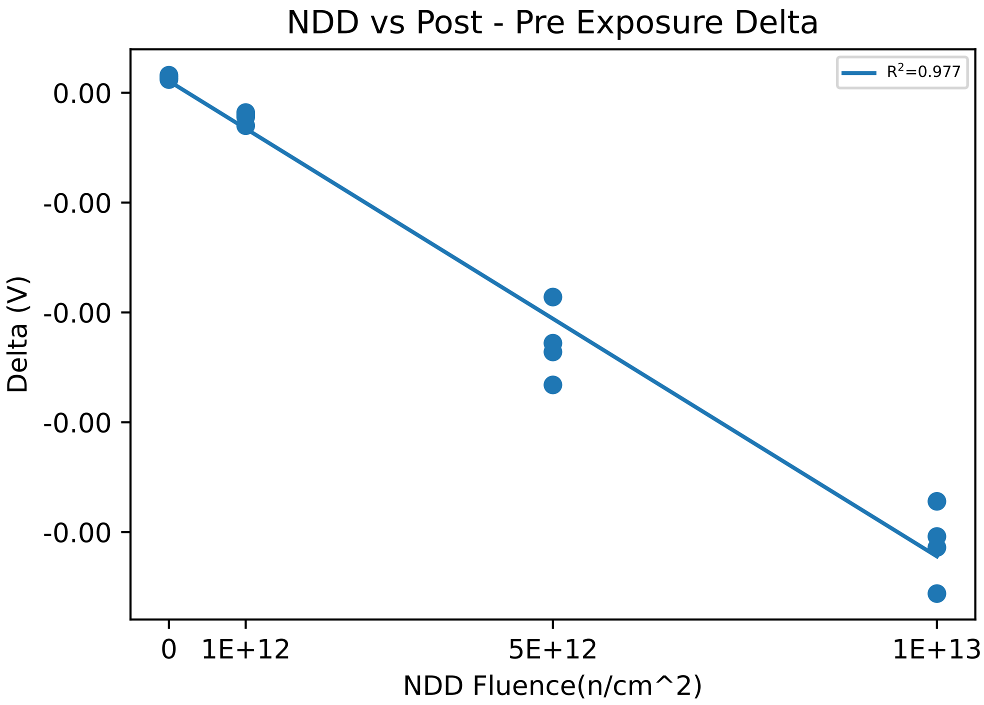
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.4131	0.4778	0.0647
2	1e+12	NDD	0.3228	0.3916	0.0688
3	1e+12	NDD	1.0488	1.0883	0.0395
4	1e+12	NDD	0.0787	0.1479	0.0692
5	5e+12	NDD	0.2357	0.287	0.0513
6	5e+12	NDD	-0.4575	-0.4079	0.0496
7	5e+12	NDD	0.3009	0.3611	0.0602
8	5e+12	NDD	0.4649	0.5009	0.036
9	1e+13	NDD	0.9889	1.0376	0.0487
10	1e+13	NDD	0.6588	0.7542	0.0954
11	1e+13	NDD	0.6739	0.725	0.0511
12	1e+13	NDD	-0.5528	-0.5392	0.0136
13	0	CORRELATION	1.2005	1.2594	0.0589
14	0	CORRELATION	-0.0183	0.0177	0.036
15	0	CORRELATION	-0.0697	-0.0259	0.0438

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0697	0.37083	1.2005	0.71897	-0.0259	0.41707	1.2594	0.72981	0.036	0.046233	0.0589	0.011642
1e+12	0.0787	0.46585	1.0488	0.41351	0.1479	0.5264	1.0883	0.3998	0.0395	0.06055	0.0692	0.01418
5e+12	-0.4575	0.136	0.4649	0.40725	-0.4079	0.18527	0.5009	0.40527	0.036	0.049275	0.0602	0.0099965
1e+13	-0.5528	0.4422	0.9889	0.68057	-0.5392	0.4944	1.0376	0.70334	0.0136	0.0522	0.0954	0.033514

Device Test: 19.58 VOLTAGE|VREF//14/14/0/0/5/1MHz//@VREF_25C





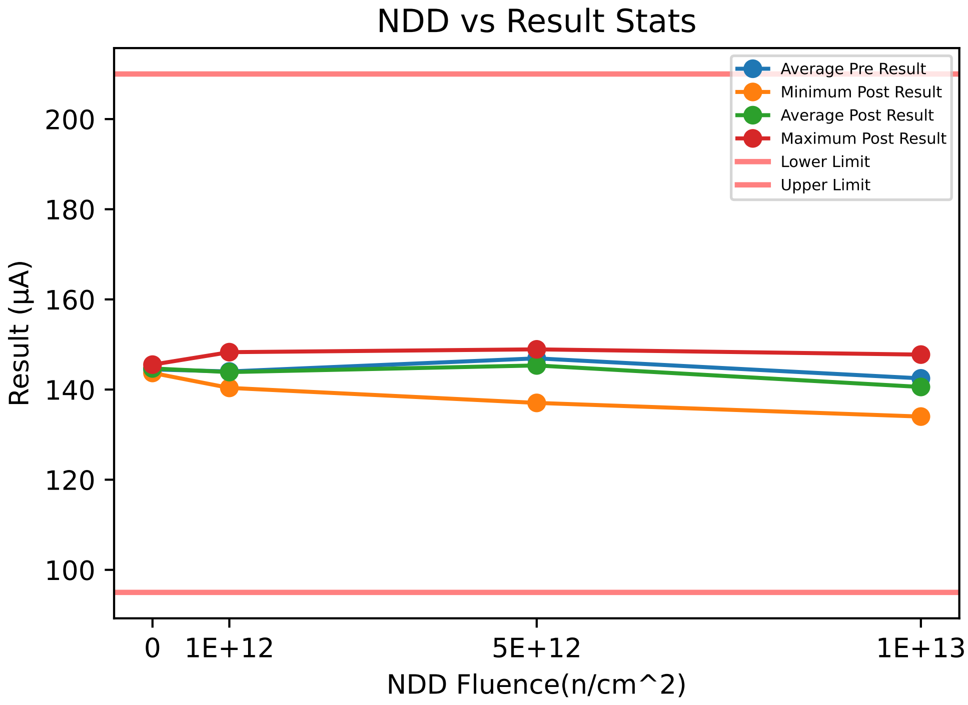
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

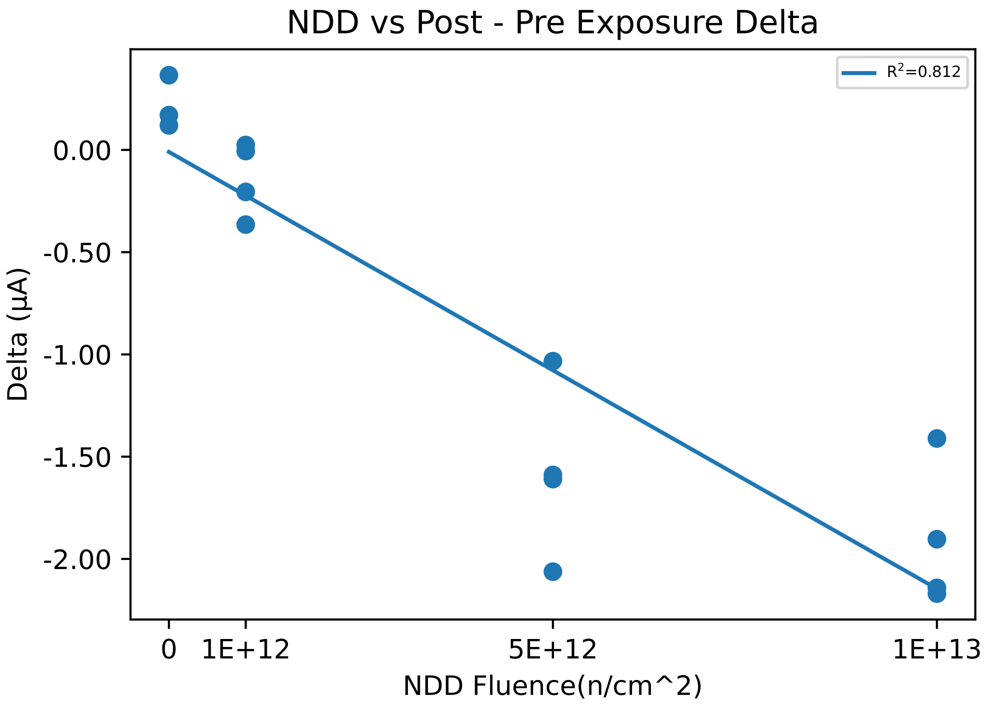
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59982	0.59973	-9e-05
2	1e+12	NDD	0.60005	0.59995	-0.0001
3	1e+12	NDD	0.60002	0.59987	-0.00015
4	1e+12	NDD	0.60042	0.60031	-0.00011
5	5e+12	NDD	0.60036	0.59918	-0.00118
6	5e+12	NDD	0.60039	0.59925	-0.00114
7	5e+12	NDD	0.60024	0.59931	-0.00093
8	5e+12	NDD	0.60002	0.59869	-0.00133
9	1e+13	NDD	0.60008	0.59801	-0.00207
10	1e+13	NDD	0.59989	0.59787	-0.00202
11	1e+13	NDD	0.60003	0.59817	-0.00186
12	1e+13	NDD	0.60001	0.59773	-0.00228
13	0	CORRELATION	0.59988	0.59996	8e-05
14	0	CORRELATION	0.59998	0.60005	7e-05
15	0	CORRELATION	0.6001	0.60016	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59988	0.59999	0.6001	0.00011015	0.59996	0.60006	0.60016	0.00010017	6e-05	7e-05	8e-05	1e-05
1e+12	0.59982	0.60008	0.60042	0.00025012	0.59973	0.59996	0.60031	0.00024732	-0.00015	-0.0001125	-9e-05	2.63e-05
5e+12	0.60002	0.60025	0.60039	0.000168	0.59869	0.59911	0.59931	0.00028336	-0.00133	-0.001145	-0.00093	0.00016503
1e+13	0.59989	0.6	0.60008	8.0571e-05	0.59773	0.59794	0.59817	0.00018859	-0.00228	-0.0020575	-0.00186	0.00017328

Device Test: 19.6 CURRENT|EA_SOURCE//5/5/0/0/5/500kHz//@EA_I_SOURCE





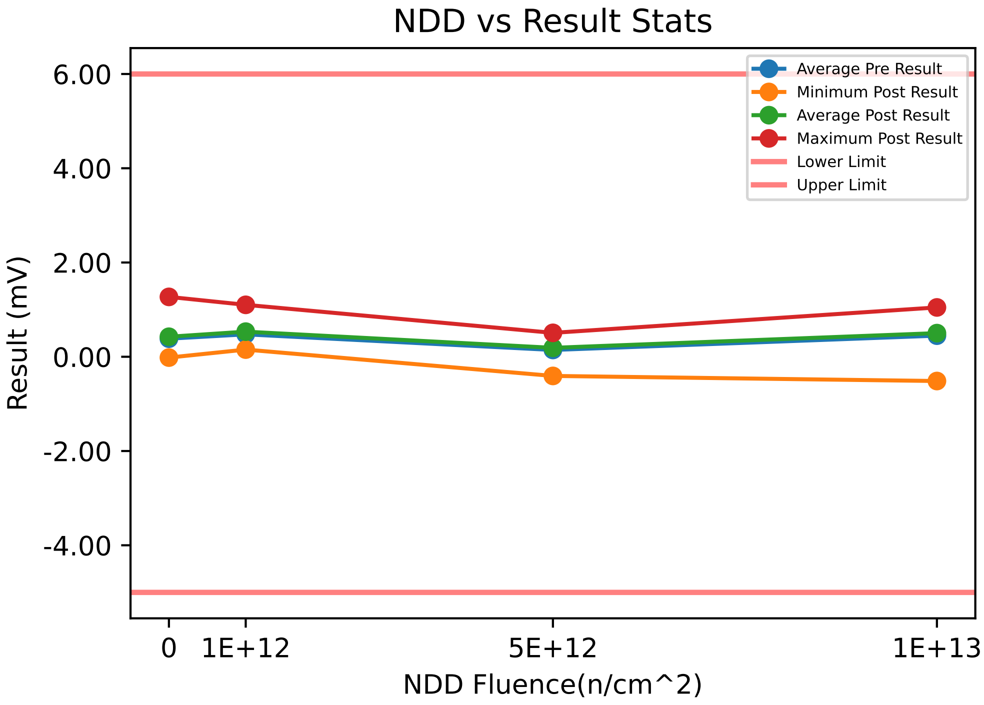
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

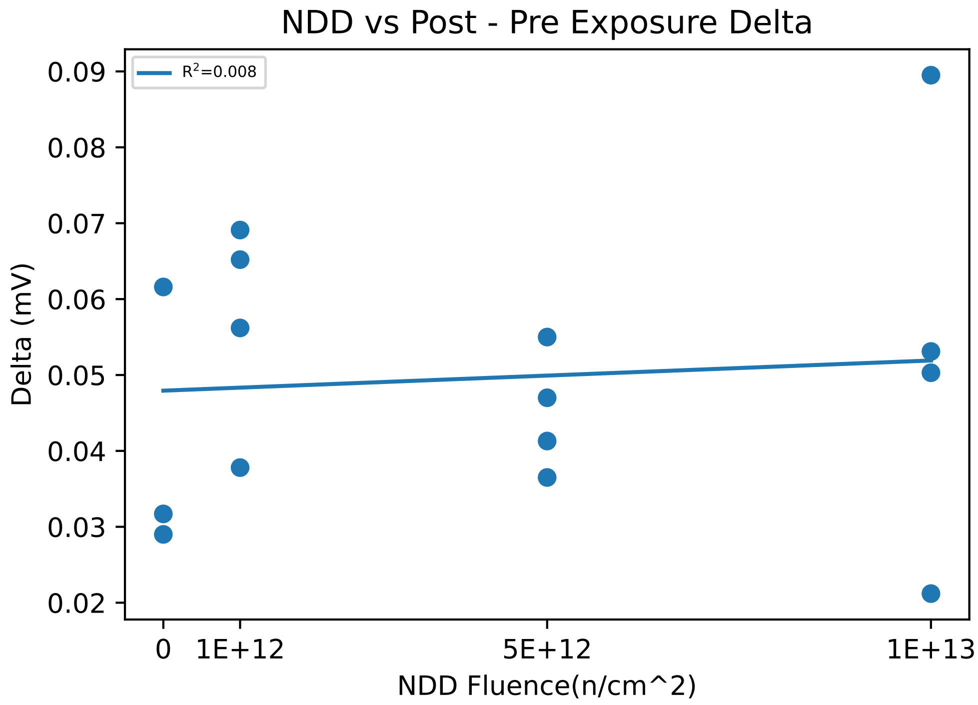
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	145.04	145.03	-0.0056
2	1e+12	NDD	140.73	140.37	-0.3652
3	1e+12	NDD	148.27	148.29	0.0241
4	1e+12	NDD	142	141.79	-0.2054
5	5e+12	NDD	150.51	148.92	-1.5892
6	5e+12	NDD	150.28	148.67	-1.6096
7	5e+12	NDD	147.8	146.76	-1.033
8	5e+12	NDD	139.1	137.04	-2.0624
9	1e+13	NDD	136.17	134.01	-2.1695
10	1e+13	NDD	139.02	137.61	-1.411
11	1e+13	NDD	149.66	147.75	-1.9036
12	1e+13	NDD	145.06	142.92	-2.1414
13	0	CORRELATION	143.32	143.68	0.3653
14	0	CORRELATION	145.35	145.52	0.1699
15	0	CORRELATION	144.72	144.84	0.1196

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.32	144.46	145.35	1.0423	143.68	144.68	145.52	0.93076	0.1196	0.21827	0.3653	0.12979
1e+12	140.73	144.01	148.27	3.3647	140.37	143.87	148.29	3.5344	-0.3652	-0.13803	0.0241	0.18255
5e+12	139.1	146.92	150.51	5.356	137.04	145.35	148.92	5.6223	-2.0624	-1.5736	-1.033	0.42139
1e+13	136.17	142.48	149.66	6.0524	134.01	140.57	147.75	6.0273	-2.1695	-1.9064	-1.411	0.35113

Device Test: 19.60 VOLTAGE|OFFSET//14/14/0/0/5/1MHz//@EA_OS





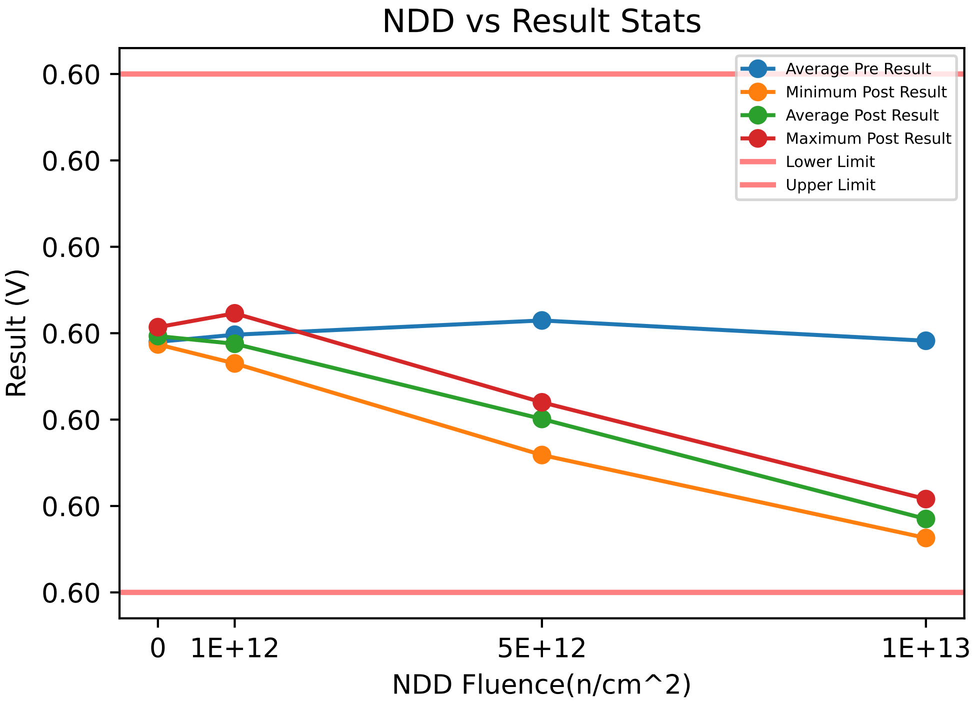
Test Results (Lower Limit = -5.0, Upper Limit = 6.0 (mV))

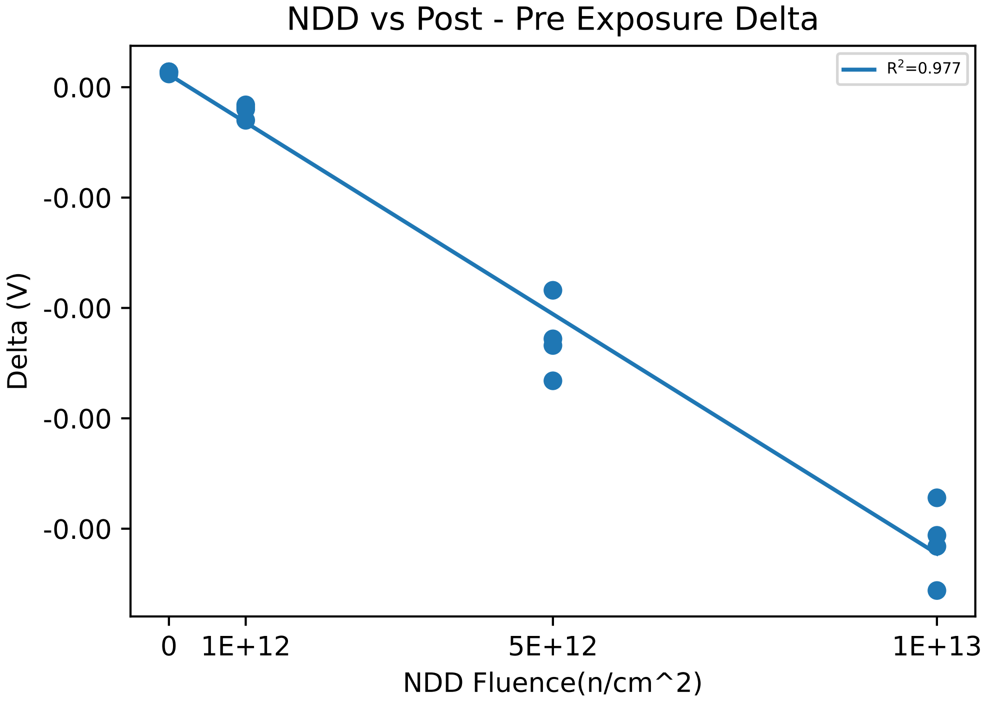
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.4233	0.4795	0.0562
2	1e+12	NDD	0.3325	0.3977	0.0652
3	1e+12	NDD	1.0641	1.1019	0.0378
4	1e+12	NDD	0.0831	0.1522	0.0691
5	5e+12	NDD	0.2492	0.2905	0.0413
6	5e+12	NDD	-0.4537	-0.4067	0.047
7	5e+12	NDD	0.312	0.367	0.055
8	5e+12	NDD	0.4708	0.5073	0.0365
9	1e+13	NDD	0.9936	1.0467	0.0531
10	1e+13	NDD	0.661	0.7505	0.0895
11	1e+13	NDD	0.6731	0.7234	0.0503
12	1e+13	NDD	-0.5359	-0.5147	0.0212
13	0	CORRELATION	1.2089	1.2705	0.0616
14	0	CORRELATION	-0.0083	0.0207	0.029
15	0	CORRELATION	-0.049	-0.0173	0.0317

Test Statistics (mV)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.049	0.38387	1.2089	0.71479	-0.0173	0.42463	1.2705	0.73279	0.029	0.040767	0.0616	0.018093
1e+12	0.0831	0.47575	1.0641	0.41777	0.1522	0.53282	1.1019	0.40407	0.0378	0.057075	0.0691	0.013939
5e+12	-0.4537	0.14458	0.4708	0.40961	-0.4067	0.18952	0.5073	0.4075	0.0365	0.04495	0.055	0.0079568
1e+13	-0.5359	0.44795	0.9936	0.67374	-0.5147	0.50148	1.0467	0.6931	0.0212	0.053525	0.0895	0.027986

Device Test: 19.61 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/100kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

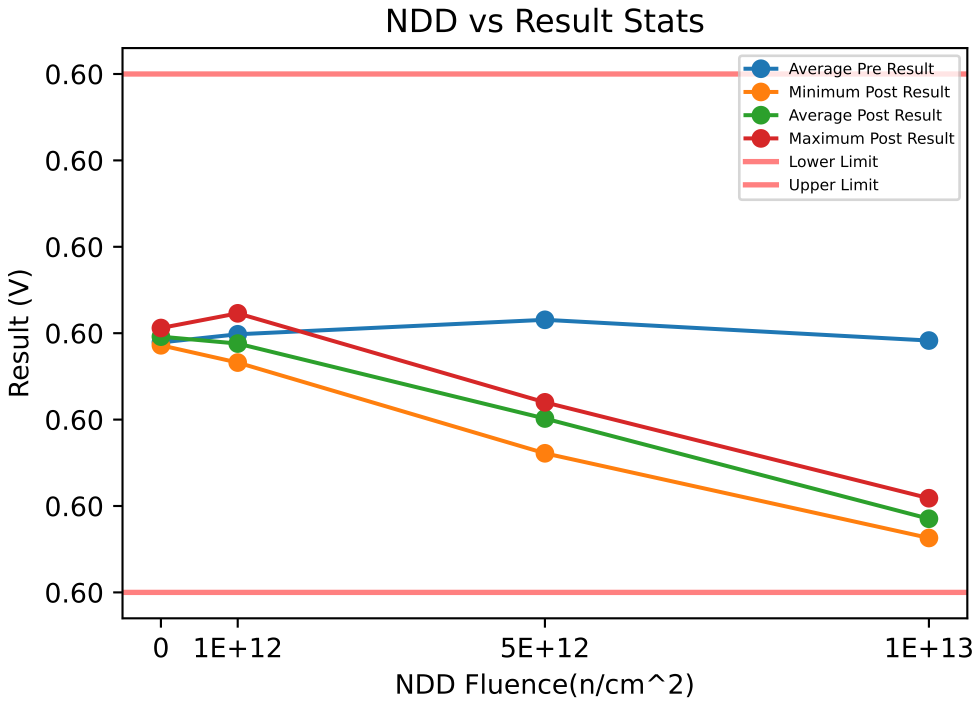
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

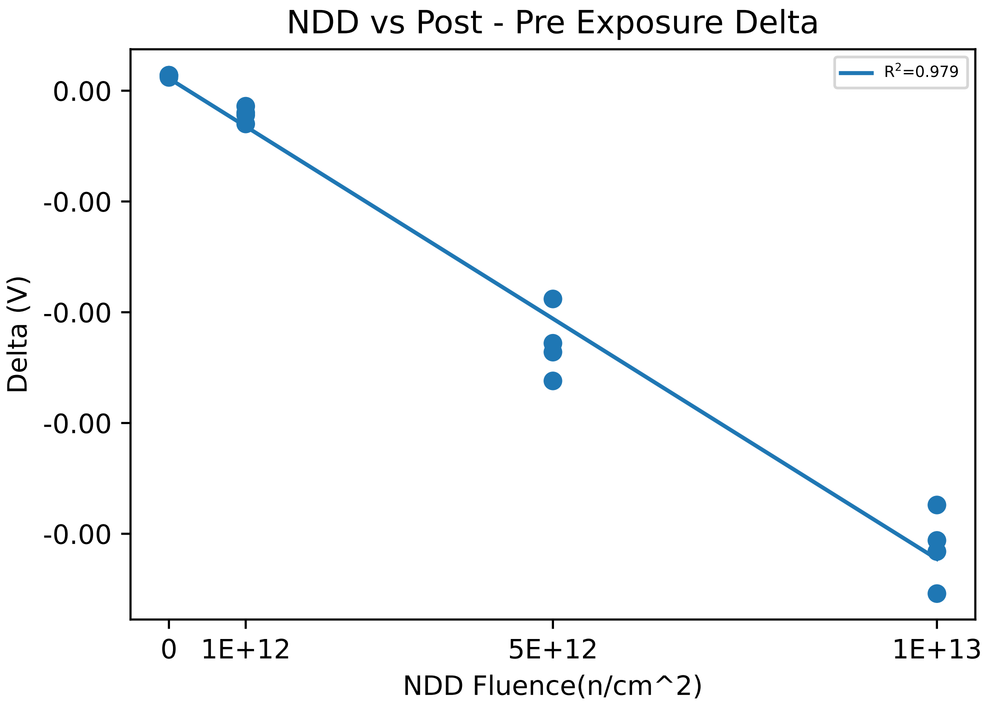
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59974	0.59965	-9e-05
2	1e+12	NDD	0.59994	0.59986	-8e-05
3	1e+12	NDD	0.59992	0.59977	-0.00015
4	1e+12	NDD	0.60033	0.60023	-0.0001
5	5e+12	NDD	0.60026	0.59909	-0.00117
6	5e+12	NDD	0.60029	0.59915	-0.00114
7	5e+12	NDD	0.60012	0.5992	-0.00092
8	5e+12	NDD	0.59992	0.59859	-0.00133
9	1e+13	NDD	0.59999	0.59791	-0.00208
10	1e+13	NDD	0.59981	0.59778	-0.00203
11	1e+13	NDD	0.59994	0.59808	-0.00186
12	1e+13	NDD	0.59991	0.59763	-0.00228
13	0	CORRELATION	0.5998	0.59987	7e-05
14	0	CORRELATION	0.5999	0.59996	6e-05
15	0	CORRELATION	0.6	0.60007	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.6	0.0001	0.59987	0.59997	0.60007	0.00010017	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.59974	0.59998	0.60033	0.00024851	0.59965	0.59988	0.60023	0.00025025	-0.00015	-0.000105	-8e-05	3.1091e-05
5e+12	0.59992	0.60015	0.60029	0.00016879	0.59859	0.59901	0.5992	0.00028194	-0.00133	-0.00114	-0.00092	0.00016872
1e+13	0.59981	0.59991	0.59999	7.5884e-05	0.59763	0.59785	0.59808	0.00019131	-0.00228	-0.0020625	-0.00186	0.00017289

Device Test: 19.63 VOLTAGE|VREF//5/5/0/1000/5/100kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

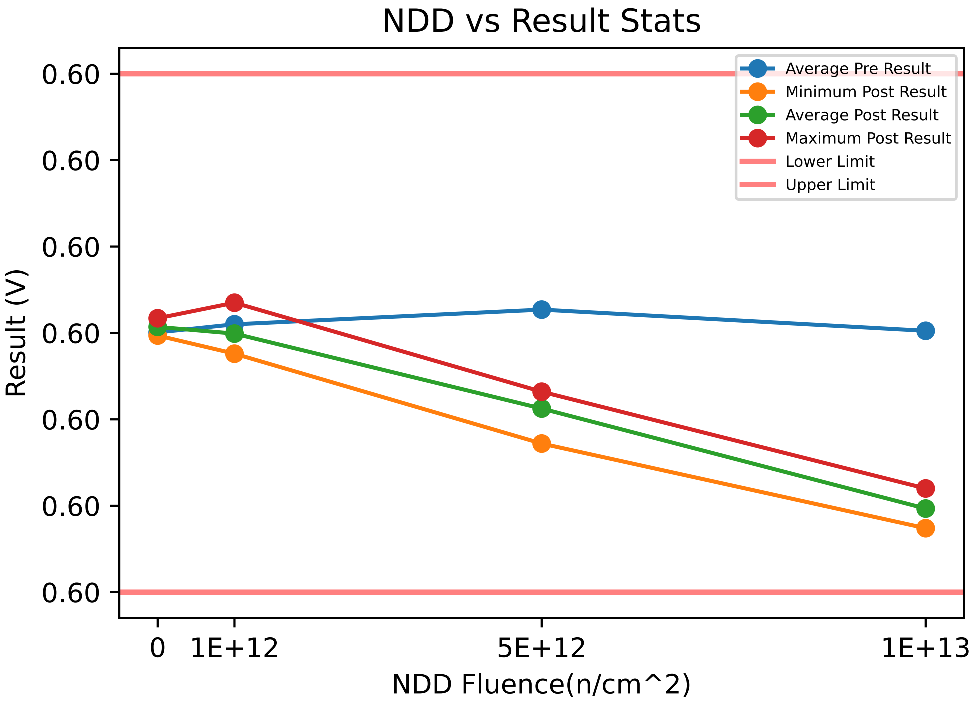
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59973	0.59966	-7e-05
2	1e+12	NDD	0.59996	0.59986	-0.0001
3	1e+12	NDD	0.59992	0.59977	-0.00015
4	1e+12	NDD	0.60034	0.60023	-0.00011
5	5e+12	NDD	0.60027	0.59909	-0.00118
6	5e+12	NDD	0.60029	0.59915	-0.00114
7	5e+12	NDD	0.60014	0.5992	-0.00094
8	5e+12	NDD	0.59992	0.59861	-0.00131
9	1e+13	NDD	0.59999	0.59791	-0.00208
10	1e+13	NDD	0.59981	0.59778	-0.00203
11	1e+13	NDD	0.59996	0.59809	-0.00187
12	1e+13	NDD	0.5999	0.59763	-0.00227
13	0	CORRELATION	0.59979	0.59986	7e-05
14	0	CORRELATION	0.5999	0.59996	6e-05
15	0	CORRELATION	0.59999	0.60006	7e-05

Test Statistics (V)

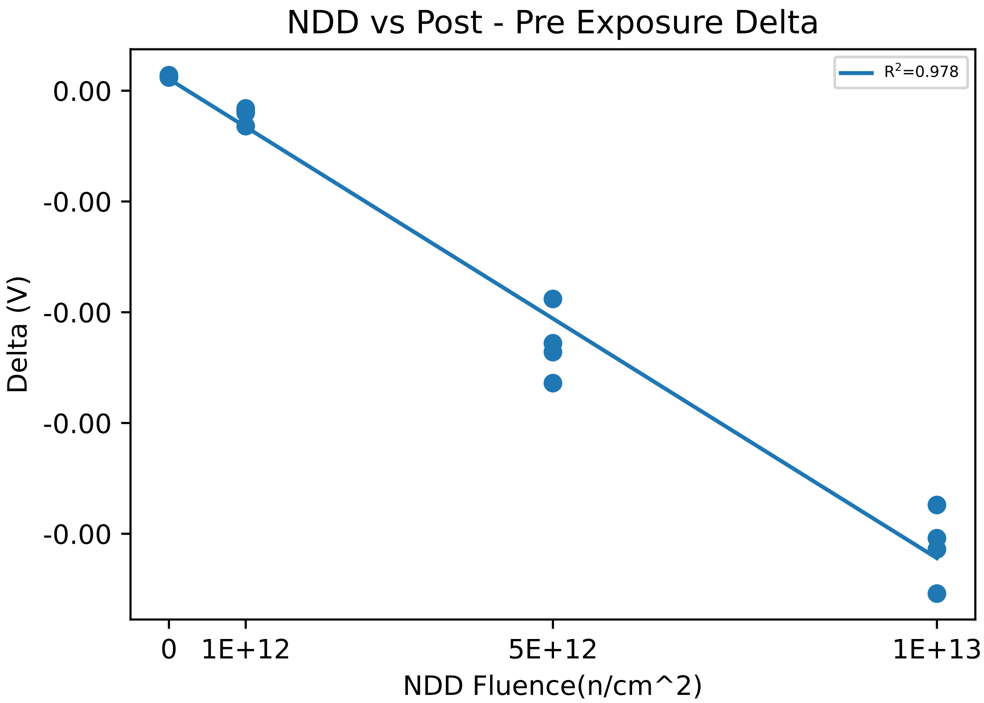
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59979	0.59989	0.59999	0.00010017	0.59986	0.59996	0.60006	0.0001	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.59973	0.59999	0.60034	0.00025552	0.59966	0.59988	0.60023	0.00024725	-0.00015	-0.0001075	-7e-05	3.304e-05
5e+12	0.59992	0.60015	0.60029	0.0001702	0.59861	0.59901	0.5992	0.00027208	-0.00131	-0.0011425	-0.00094	0.00015327
1e+13	0.59981	0.59991	0.59999	7.9373e-05	0.59763	0.59785	0.59809	0.00019534	-0.00227	-0.0020625	-0.00187	0.0001648

Device Test: 19.65 VOLTAGE|VREF//12/12/0/1000/5/100kHz//@VREF_25C



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

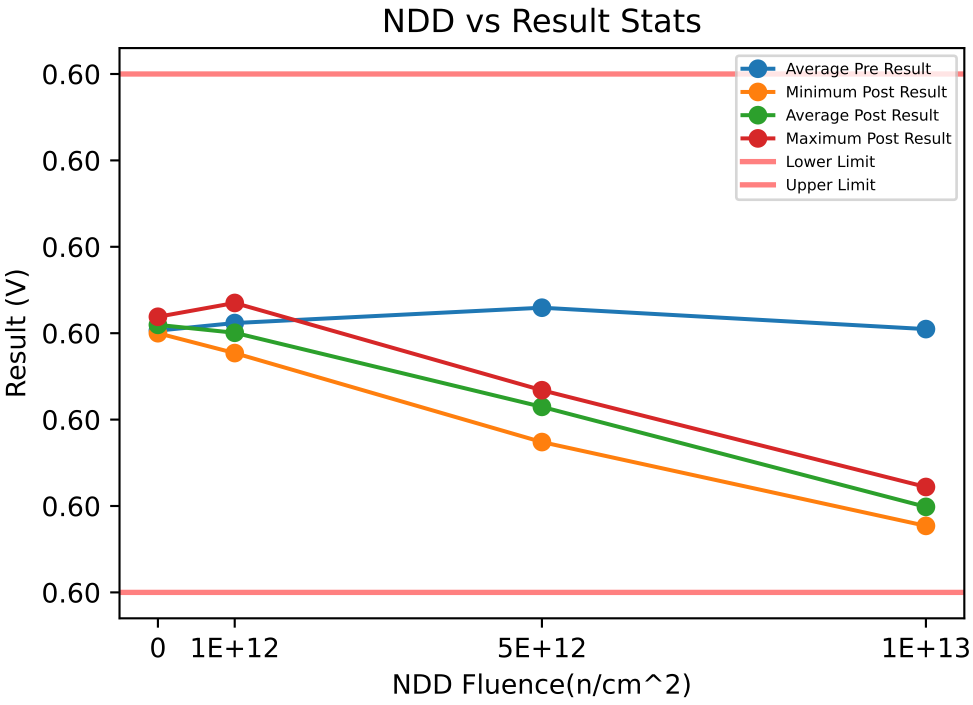
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59986	0.59976	-0.0001
2	1e+12	NDD	0.60006	0.59998	-8e-05
3	1e+12	NDD	0.60004	0.59988	-0.00016
4	1e+12	NDD	0.60044	0.60035	-9e-05
5	5e+12	NDD	0.60038	0.5992	-0.00118
6	5e+12	NDD	0.6004	0.59926	-0.00114
7	5e+12	NDD	0.60026	0.59932	-0.00094
8	5e+12	NDD	0.60004	0.59872	-0.00132
9	1e+13	NDD	0.6001	0.59803	-0.00207
10	1e+13	NDD	0.59992	0.5979	-0.00202
11	1e+13	NDD	0.60007	0.5982	-0.00187
12	1e+13	NDD	0.60001	0.59774	-0.00227
13	0	CORRELATION	0.5999	0.59997	7e-05
14	0	CORRELATION	0.60001	0.60007	6e-05
15	0	CORRELATION	0.60011	0.60017	6e-05

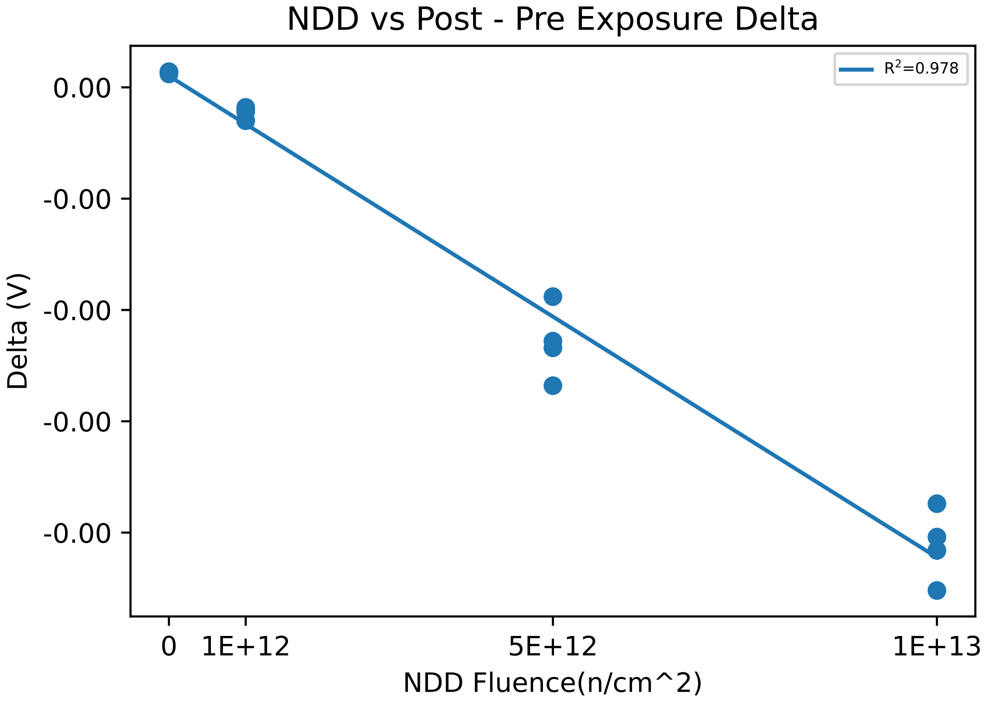


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60001	0.60011	0.00010504	0.59997	0.60007	0.60017	0.0001	6e-05	6.3333e-05	7e-05	5.7735e-06
1e+12	0.59986	0.6001	0.60044	0.00024386	0.59976	0.59999	0.60035	0.00025474	-0.00016	-0.0001075	-8e-05	3.594e-05
5e+12	0.60004	0.60027	0.6004	0.00016533	0.59872	0.59913	0.59932	0.00027441	-0.00132	-0.001145	-0.00094	0.00015695
1e+13	0.59992	0.60003	0.6001	7.9373e-05	0.59774	0.59797	0.5982	0.00019517	-0.00227	-0.0020575	-0.00187	0.0001652

Device Test: 19.67 VOLTAGE|VREF//14/14/0/1000/5/100kHz//@VREF_25C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

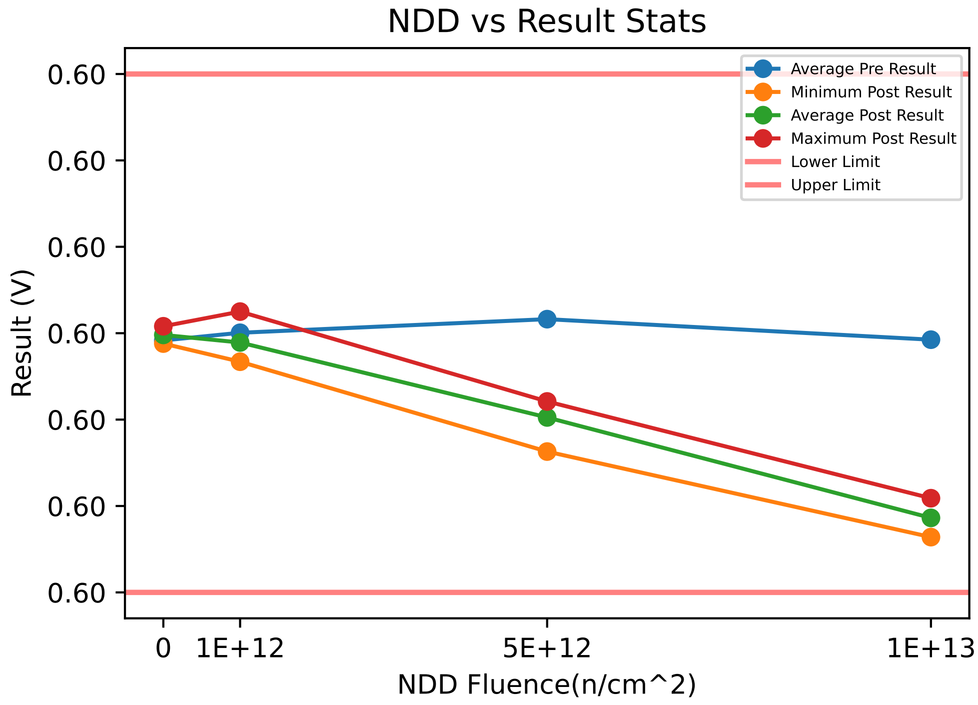
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

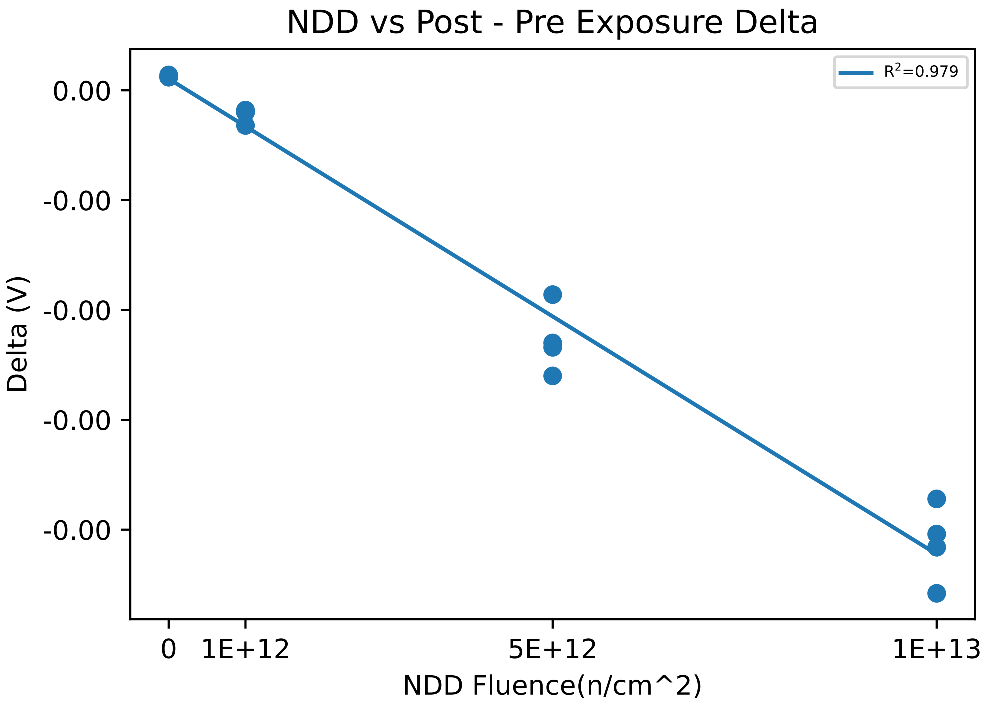
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59987	0.59977	-0.0001
2	1e+12	NDD	0.60009	0.6	-9e-05
3	1e+12	NDD	0.60005	0.5999	-0.00015
4	1e+12	NDD	0.60046	0.60035	-0.00011
5	5e+12	NDD	0.60039	0.59922	-0.00117
6	5e+12	NDD	0.60043	0.59929	-0.00114
7	5e+12	NDD	0.60028	0.59934	-0.00094
8	5e+12	NDD	0.60008	0.59874	-0.00134
9	1e+13	NDD	0.60013	0.59805	-0.00208
10	1e+13	NDD	0.59994	0.59792	-0.00202
11	1e+13	NDD	0.60009	0.59822	-0.00187
12	1e+13	NDD	0.60003	0.59777	-0.00226
13	0	CORRELATION	0.59993	0.6	7e-05
14	0	CORRELATION	0.60004	0.6001	6e-05
15	0	CORRELATION	0.60012	0.60019	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59993	0.60003	0.60012	9.5394e-05	0.6	0.6001	0.60019	9.5044e-05	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.59987	0.60012	0.60046	0.00024757	0.59977	0.60001	0.60035	0.00024853	-0.00015	-0.0001125	-9e-05	2.63e-05
5e+12	0.60008	0.6003	0.60043	0.00015674	0.59874	0.59915	0.59934	0.00027609	-0.00134	-0.0011475	-0.00094	0.00016399
1e+13	0.59994	0.60005	0.60013	8.2614e-05	0.59777	0.59799	0.59822	0.00019131	-0.00226	-0.0020575	-0.00187	0.00016132

Device Test: 19.69 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/500kHz//@VREF_25C





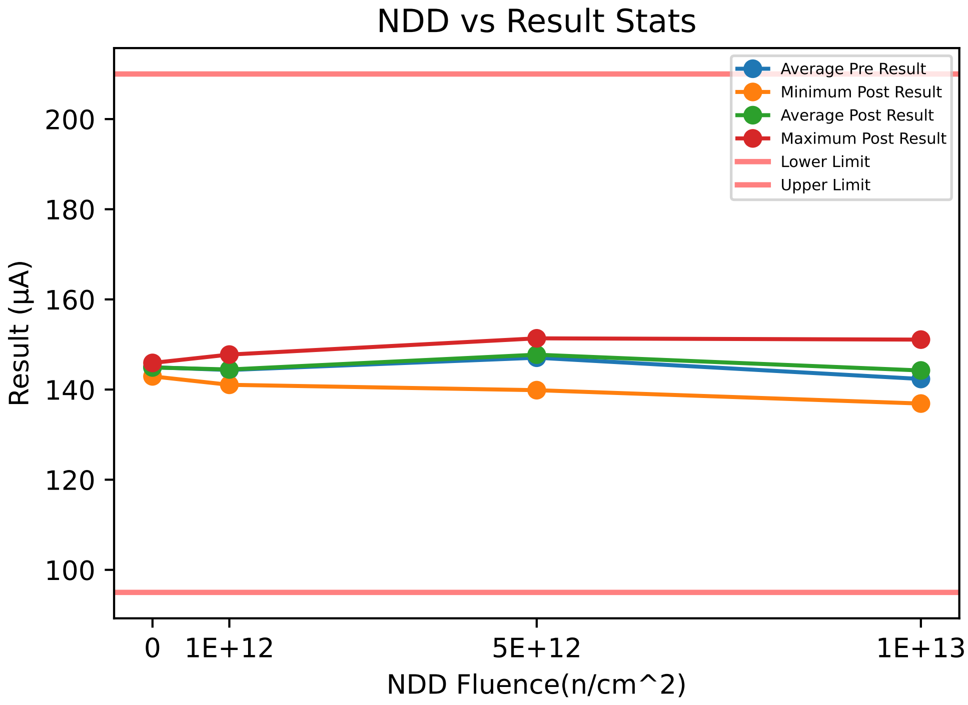
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

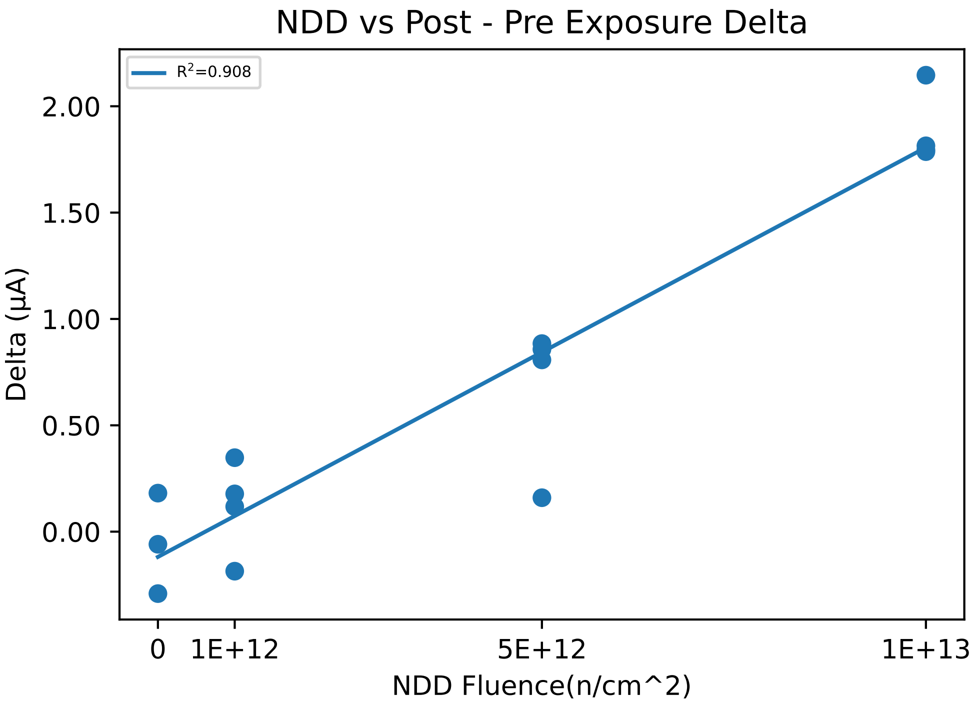
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59976	0.59967	-9e-05
2	1e+12	NDD	0.59997	0.59987	-0.0001
3	1e+12	NDD	0.59994	0.59978	-0.00016
4	1e+12	NDD	0.60035	0.60025	-0.0001
5	5e+12	NDD	0.60027	0.5991	-0.00117
6	5e+12	NDD	0.60031	0.59916	-0.00115
7	5e+12	NDD	0.60014	0.59921	-0.00093
8	5e+12	NDD	0.59993	0.59863	-0.0013
9	1e+13	NDD	0.6	0.59792	-0.00208
10	1e+13	NDD	0.59982	0.5978	-0.00202
11	1e+13	NDD	0.59995	0.59809	-0.00186
12	1e+13	NDD	0.59993	0.59764	-0.00229
13	0	CORRELATION	0.59981	0.59988	7e-05
14	0	CORRELATION	0.59992	0.59998	6e-05
15	0	CORRELATION	0.60002	0.60008	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59981	0.59992	0.60002	0.00010504	0.59988	0.59998	0.60008	0.0001	6e-05	6.3333e-05	7e-05	5.7735e-06
1e+12	0.59976	0.60001	0.60035	0.00024799	0.59967	0.59989	0.60025	0.00025198	-0.00016	-0.0001125	-9e-05	3.2016e-05
5e+12	0.59993	0.60016	0.60031	0.00017115	0.59863	0.59903	0.59921	0.00026715	-0.0013	-0.0011375	-0.00093	0.00015349
1e+13	0.59982	0.59993	0.6	7.5939e-05	0.59764	0.59786	0.59809	0.00019015	-0.00229	-0.0020625	-0.00186	0.00017783

Device Test: 19.7 CURRENT|EA_SINK//5/5/0/0/5/500kHz//@EA_I_SINK





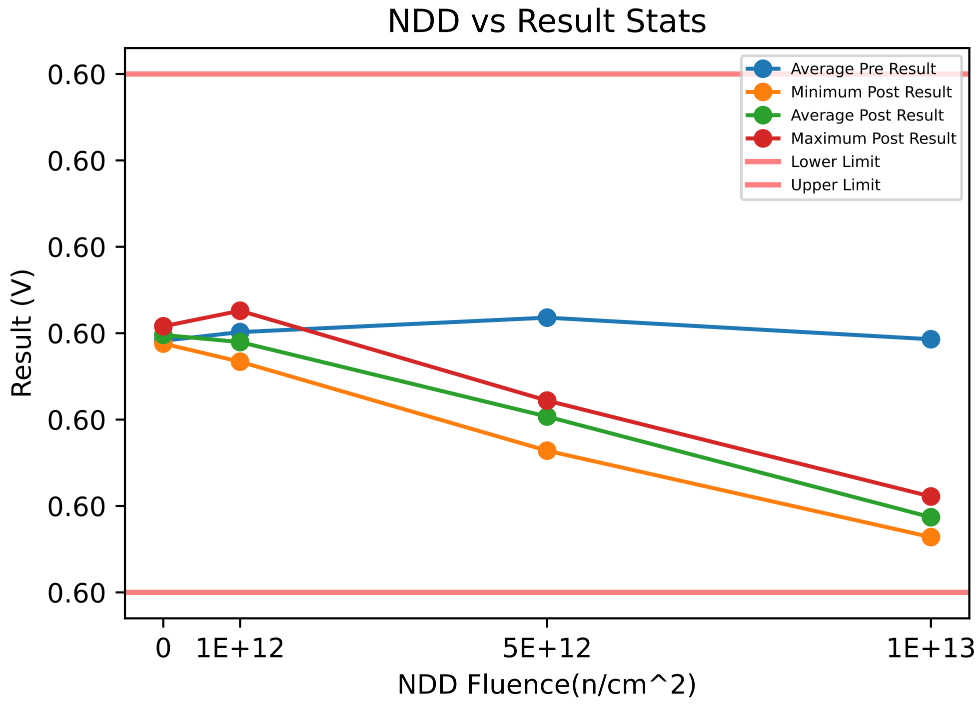
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

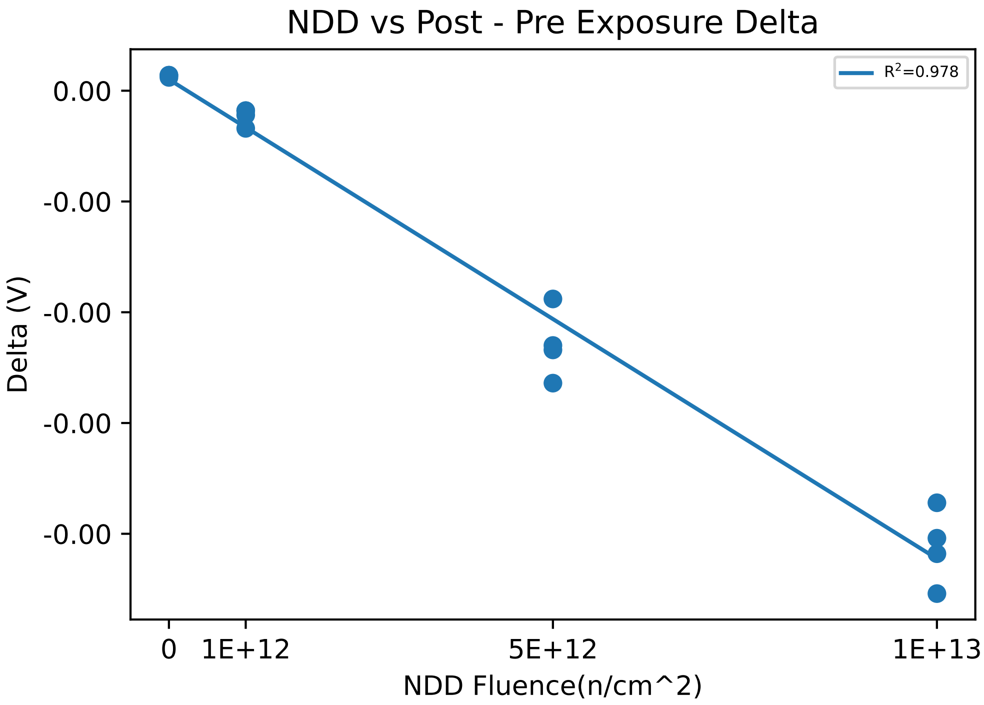
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	146	146.35	0.3478
2	1e+12	NDD	141.24	141.05	-0.1858
3	1e+12	NDD	147.64	147.76	0.1177
4	1e+12	NDD	142.46	142.64	0.1776
5	5e+12	NDD	150.48	151.36	0.8842
6	5e+12	NDD	150.28	151.09	0.8076
7	5e+12	NDD	147.79	148.64	0.8573
8	5e+12	NDD	139.7	139.86	0.1596
9	1e+13	NDD	135.11	136.89	1.7866
10	1e+13	NDD	139.08	141.23	2.146
11	1e+13	NDD	149.28	151.08	1.7954
12	1e+13	NDD	145.91	147.73	1.814
13	0	CORRELATION	143.21	142.92	-0.2912
14	0	CORRELATION	145.92	145.86	-0.0593
15	0	CORRELATION	145.72	145.91	0.1812

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.21	144.95	145.92	1.5091	142.92	144.9	145.91	1.7093	-0.2912	-0.056433	0.1812	0.23621
1e+12	141.24	144.34	147.64	2.9888	141.05	144.45	147.76	3.1289	-0.1858	0.11432	0.3478	0.22256
5e+12	139.7	147.06	150.48	5.0579	139.86	147.74	151.36	5.3927	0.1596	0.67718	0.8842	0.34651
1e+13	135.11	142.35	149.28	6.4269	136.89	144.23	151.08	6.3764	1.7866	1.8855	2.146	0.17404

Device Test: 19.71 VOLTAGE|VREF//5/5/0/1000/5/500kHz//@VREF_25C





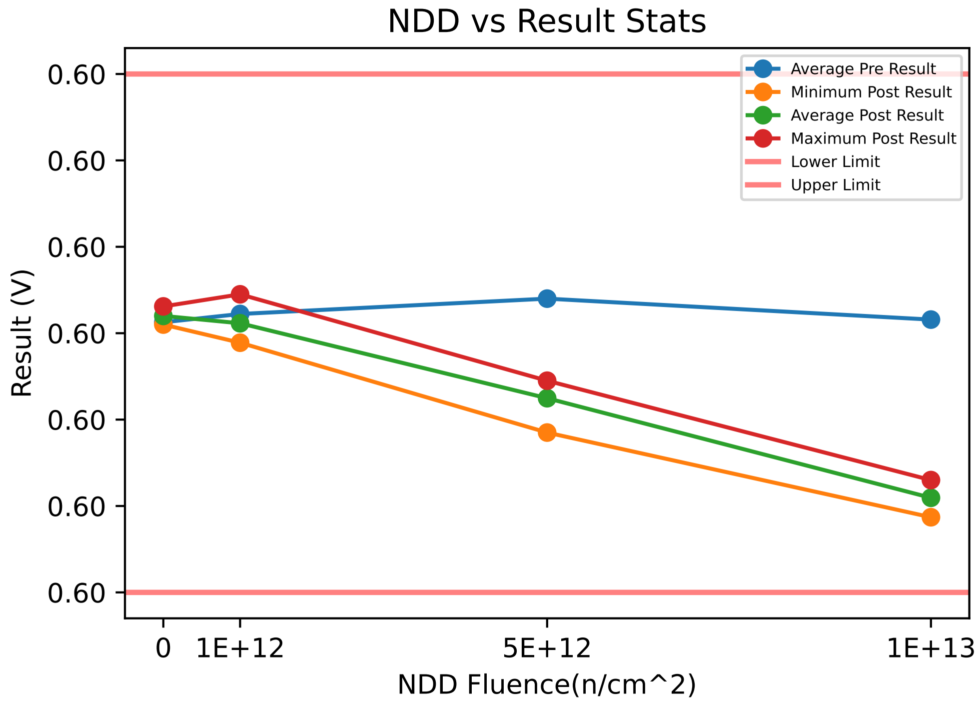
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

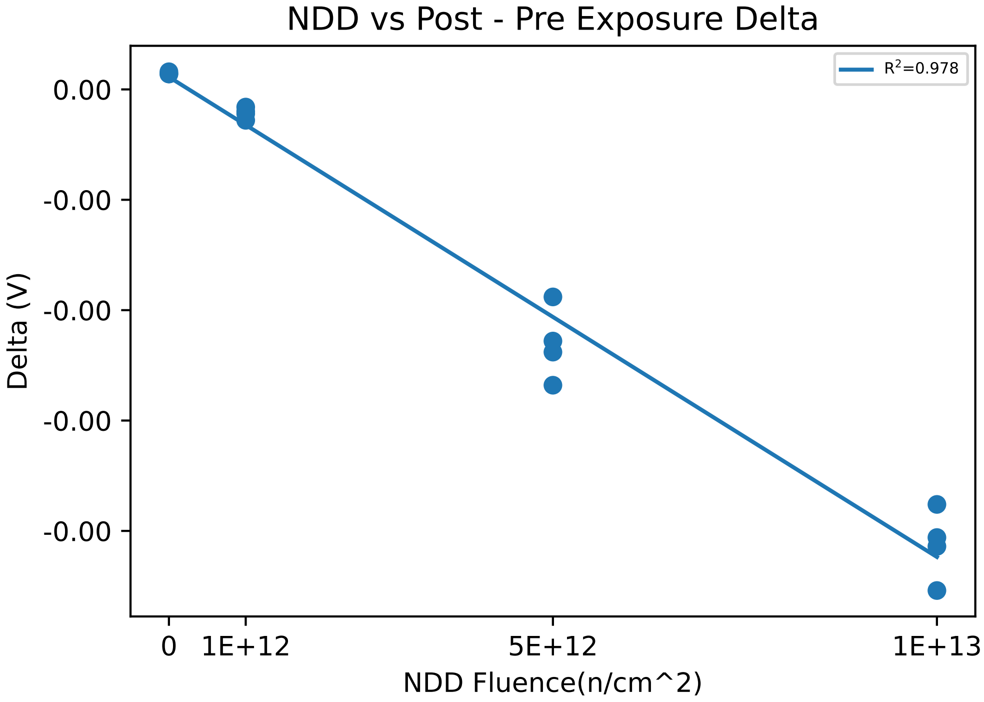
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59976	0.59967	-9e-05
2	1e+12	NDD	0.59997	0.59988	-9e-05
3	1e+12	NDD	0.59995	0.59978	-0.00017
4	1e+12	NDD	0.60037	0.60026	-0.00011
5	5e+12	NDD	0.60028	0.59911	-0.00117
6	5e+12	NDD	0.60032	0.59917	-0.00115
7	5e+12	NDD	0.60016	0.59922	-0.00094
8	5e+12	NDD	0.59996	0.59864	-0.00132
9	1e+13	NDD	0.60001	0.59792	-0.00209
10	1e+13	NDD	0.59983	0.59781	-0.00202
11	1e+13	NDD	0.59997	0.59811	-0.00186
12	1e+13	NDD	0.59991	0.59764	-0.00227
13	0	CORRELATION	0.59981	0.59988	7e-05
14	0	CORRELATION	0.59992	0.59998	6e-05
15	0	CORRELATION	0.60001	0.60008	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59981	0.59991	0.60001	0.00010017	0.59988	0.59998	0.60008	0.0001	6e-05	6.6667e-05	7e-05	5.7735e-06
1e+12	0.59976	0.60001	0.60037	0.00025643	0.59967	0.5999	0.60026	0.00025643	-0.00017	-0.000115	-9e-05	3.7859e-05
5e+12	0.59996	0.60018	0.60032	0.00016166	0.59864	0.59903	0.59922	0.00026715	-0.00132	-0.001145	-0.00094	0.00015631
1e+13	0.59983	0.59993	0.60001	7.8316e-05	0.59764	0.59787	0.59811	0.00019715	-0.00227	-0.00206	-0.00186	0.0001699

Device Test: 19.73 VOLTAGE|VREF//12/12/0/1000/5/500kHz//@VREF_25C





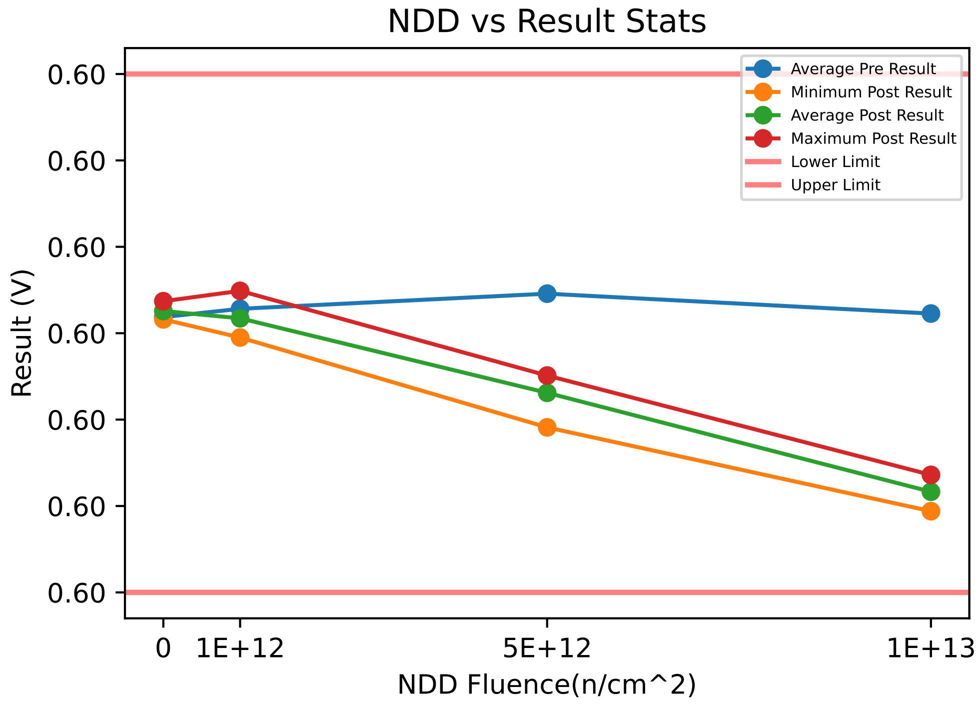
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

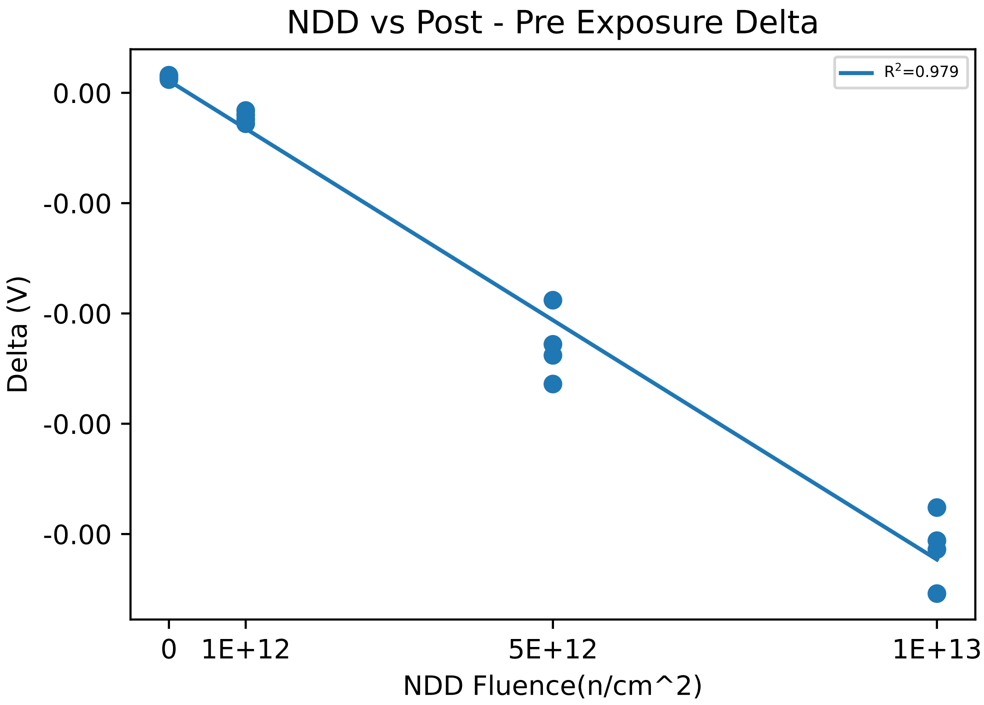
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59997	0.59989	-8e-05
2	1e+12	NDD	0.60019	0.60009	-0.0001
3	1e+12	NDD	0.60017	0.60003	-0.00014
4	1e+12	NDD	0.60056	0.60045	-0.00011
5	5e+12	NDD	0.60049	0.5993	-0.00119
6	5e+12	NDD	0.60053	0.59939	-0.00114
7	5e+12	NDD	0.60039	0.59945	-0.00094
8	5e+12	NDD	0.60019	0.59885	-0.00134
9	1e+13	NDD	0.60025	0.59818	-0.00207
10	1e+13	NDD	0.60006	0.59803	-0.00203
11	1e+13	NDD	0.60018	0.5983	-0.00188
12	1e+13	NDD	0.60014	0.59787	-0.00227
13	0	CORRELATION	0.60003	0.6001	7e-05
14	0	CORRELATION	0.60012	0.60019	7e-05
15	0	CORRELATION	0.60023	0.60031	8e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60003	0.60013	0.60023	0.00010017	0.6001	0.6002	0.60031	0.00010536	7e-05	7.3333e-05	8e-05	5.7735e-06
1e+12	0.59997	0.60022	0.60056	0.00024595	0.59989	0.60011	0.60045	0.00023854	-0.00014	-0.0001075	-8e-05	2.5e-05
5e+12	0.60019	0.6004	0.60053	0.00015188	0.59885	0.59925	0.59945	0.00027208	-0.00134	-0.0011525	-0.00094	0.0001652
1e+13	0.60006	0.60016	0.60025	7.932e-05	0.59787	0.5981	0.5983	0.00018628	-0.00227	-0.0020625	-0.00188	0.0001607

Device Test: 19.75 VOLTAGE|VREF//14/14/0/1000/5/500kHz//@VREF_25C





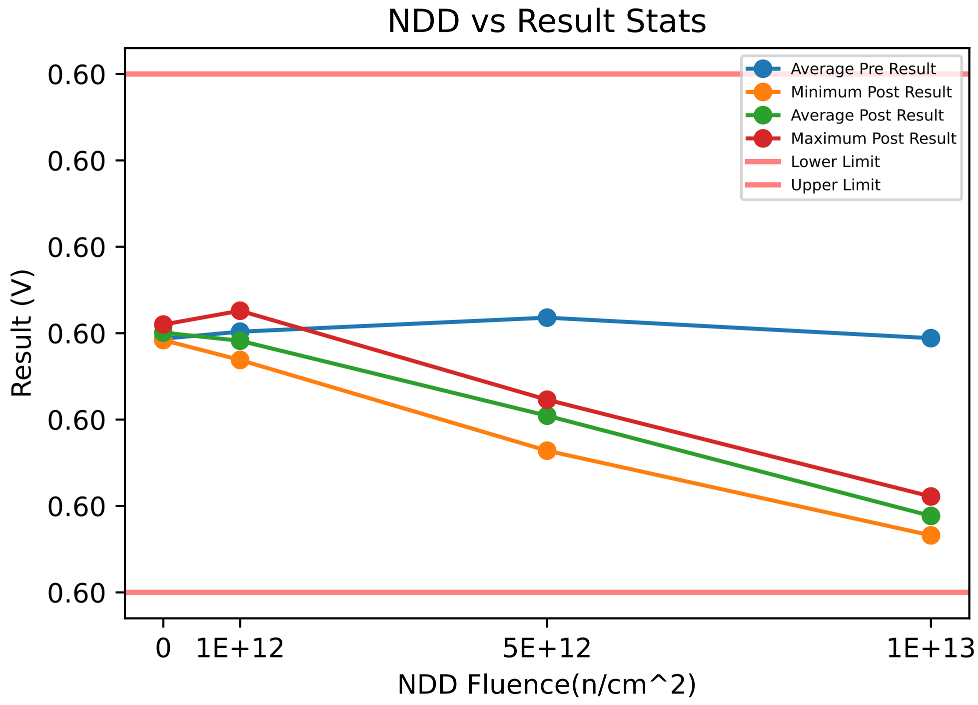
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

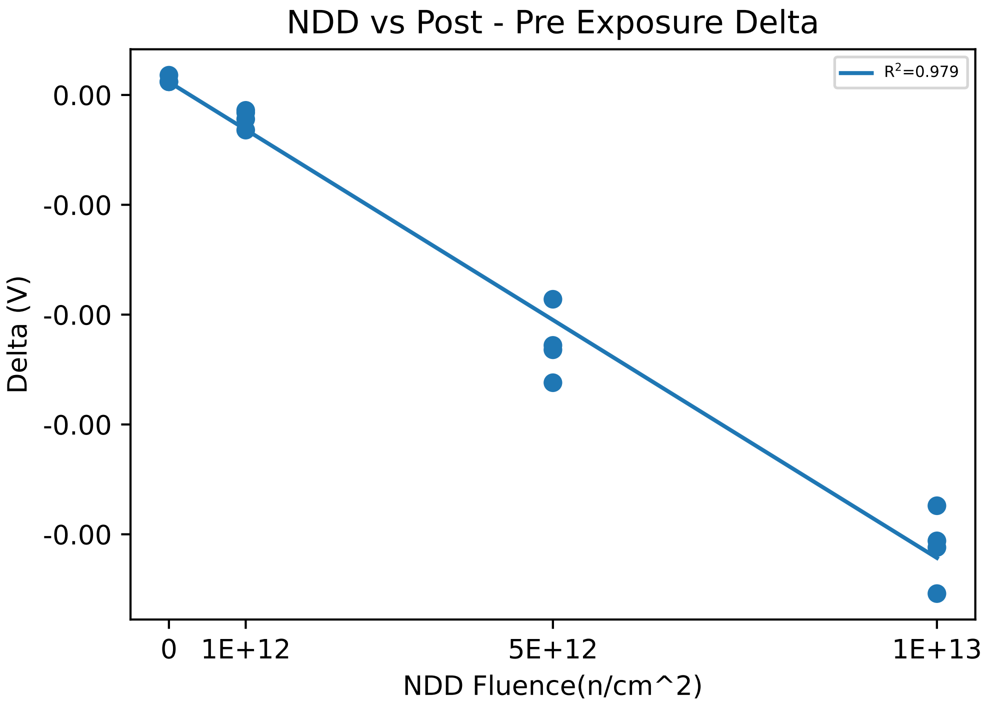
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60003	0.59995	-8e-05
2	1e+12	NDD	0.60026	0.60016	-0.0001
3	1e+12	NDD	0.60023	0.60009	-0.00014
4	1e+12	NDD	0.60061	0.60049	-0.00012
5	5e+12	NDD	0.60055	0.59936	-0.00119
6	5e+12	NDD	0.6006	0.59946	-0.00114
7	5e+12	NDD	0.60045	0.59951	-0.00094
8	5e+12	NDD	0.60023	0.59891	-0.00132
9	1e+13	NDD	0.60033	0.59826	-0.00207
10	1e+13	NDD	0.60013	0.5981	-0.00203
11	1e+13	NDD	0.60024	0.59836	-0.00188
12	1e+13	NDD	0.60021	0.59794	-0.00227
13	0	CORRELATION	0.60009	0.60016	7e-05
14	0	CORRELATION	0.60018	0.60024	6e-05
15	0	CORRELATION	0.60029	0.60037	8e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60009	0.60019	0.60029	0.00010017	0.60016	0.60026	0.60037	0.00010599	6e-05	7e-05	8e-05	1e-05
1e+12	0.60003	0.60028	0.60061	0.00024102	0.59995	0.60017	0.60049	0.00022897	-0.00014	-0.00011	-8e-05	2.582e-05
5e+12	0.60023	0.60046	0.6006	0.00016399	0.59891	0.59931	0.59951	0.00027386	-0.00132	-0.0011475	-0.00094	0.00015777
1e+13	0.60013	0.60023	0.60033	8.2614e-05	0.59794	0.59817	0.59836	0.0001843	-0.00227	-0.0020625	-0.00188	0.0001607

Device Test: 19.77 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/1MHz//@VREF_25C





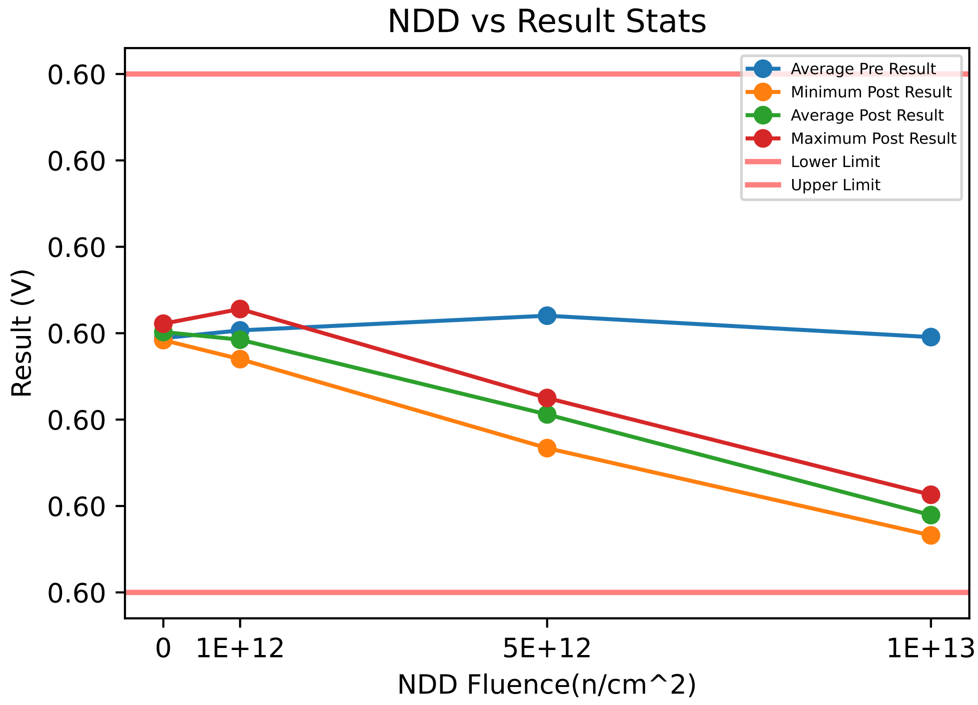
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

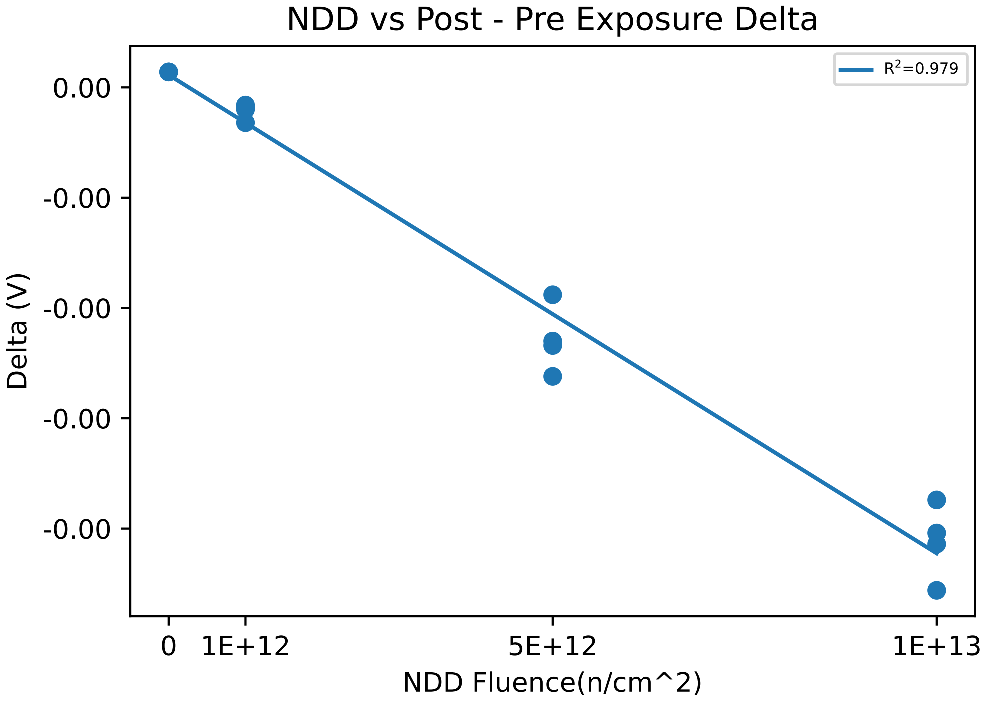
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59976	0.59969	-7e-05
2	1e+12	NDD	0.59998	0.5999	-8e-05
3	1e+12	NDD	0.59996	0.5998	-0.00016
4	1e+12	NDD	0.60037	0.60026	-0.00011
5	5e+12	NDD	0.60029	0.59913	-0.00116
6	5e+12	NDD	0.60032	0.59918	-0.00114
7	5e+12	NDD	0.60016	0.59923	-0.00093
8	5e+12	NDD	0.59995	0.59864	-0.00131
9	1e+13	NDD	0.60002	0.59796	-0.00206
10	1e+13	NDD	0.59984	0.59781	-0.00203
11	1e+13	NDD	0.59998	0.59811	-0.00187
12	1e+13	NDD	0.59993	0.59766	-0.00227
13	0	CORRELATION	0.59983	0.59992	9e-05
14	0	CORRELATION	0.59994	0.6	6e-05
15	0	CORRELATION	0.60004	0.6001	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59983	0.59994	0.60004	0.00010504	0.59992	0.60001	0.6001	9.0185e-05	6e-05	7e-05	9e-05	1.7321e-05
1e+12	0.59976	0.60002	0.60037	0.00025513	0.59969	0.59991	0.60026	0.00024703	-0.00016	-0.000105	-7e-05	4.0415e-05
5e+12	0.59995	0.60018	0.60032	0.00016833	0.59864	0.59905	0.59923	0.00027307	-0.00131	-0.001135	-0.00093	0.00015631
1e+13	0.59984	0.59994	0.60002	7.7621e-05	0.59766	0.59788	0.59811	0.00019365	-0.00227	-0.0020575	-0.00187	0.00016439

Device Test: 19.79 VOLTAGE|VREF//5/5/0/1000/5/1MHz//@VREF_25C





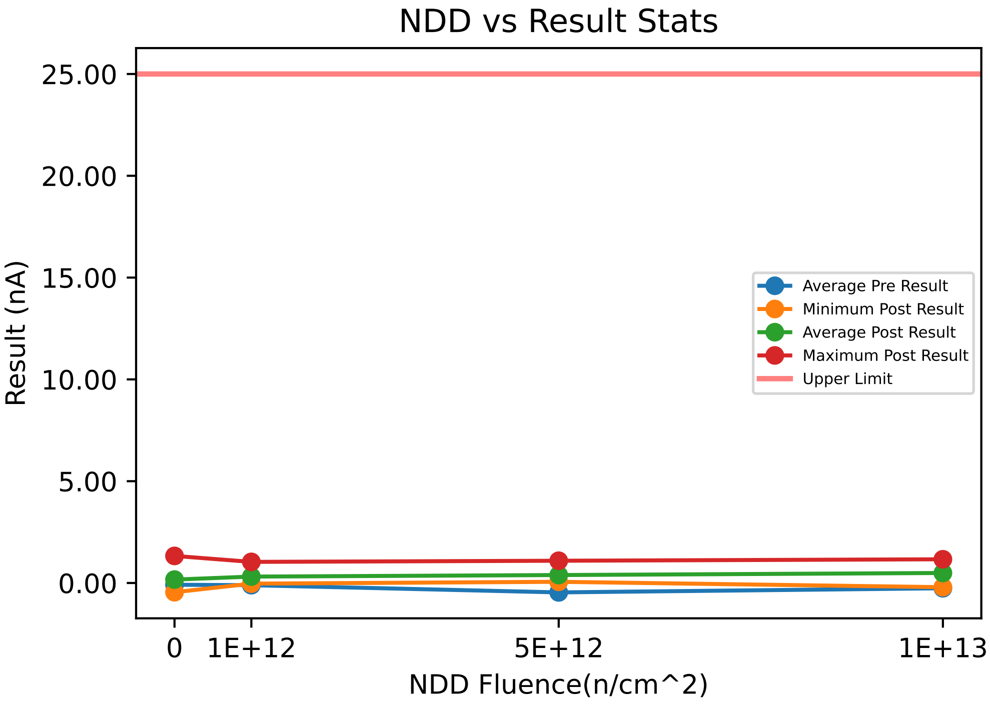
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

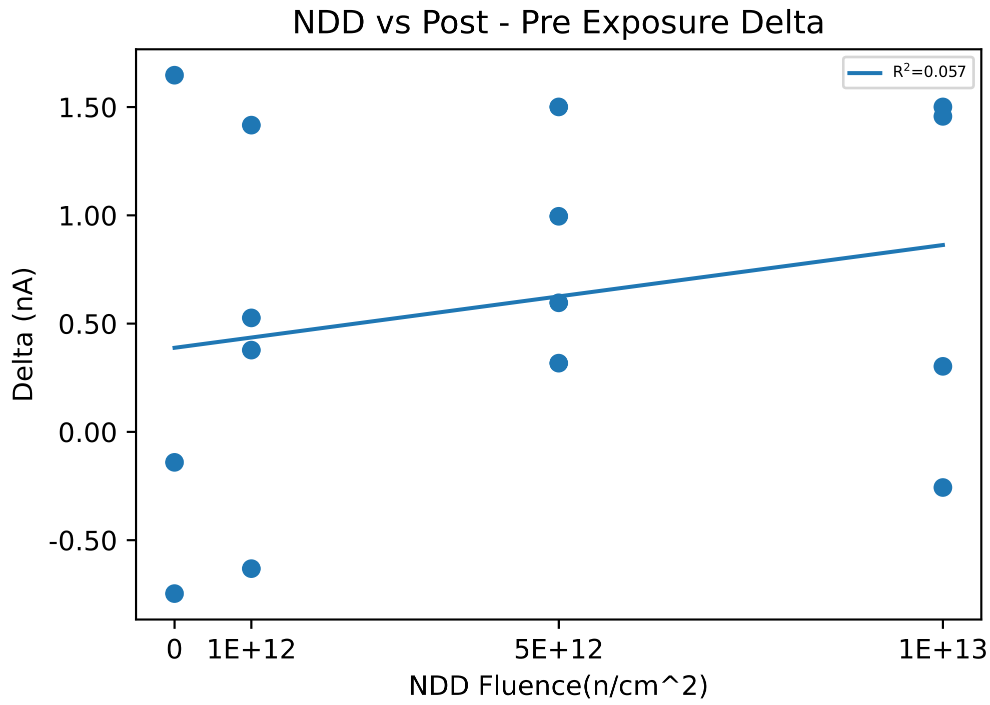
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.59978	0.5997	-8e-05
2	1e+12	NDD	0.6	0.59991	-9e-05
3	1e+12	NDD	0.59997	0.59981	-0.00016
4	1e+12	NDD	0.60038	0.60028	-0.0001
5	5e+12	NDD	0.6003	0.59913	-0.00117
6	5e+12	NDD	0.60034	0.59919	-0.00115
7	5e+12	NDD	0.60019	0.59925	-0.00094
8	5e+12	NDD	0.59998	0.59867	-0.00131
9	1e+13	NDD	0.60003	0.59796	-0.00207
10	1e+13	NDD	0.59985	0.59783	-0.00202
11	1e+13	NDD	0.6	0.59813	-0.00187
12	1e+13	NDD	0.59994	0.59766	-0.00228
13	0	CORRELATION	0.59985	0.59992	7e-05
14	0	CORRELATION	0.59994	0.60001	7e-05
15	0	CORRELATION	0.60004	0.60011	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59985	0.59994	0.60004	9.5044e-05	0.59992	0.60001	0.60011	9.5044e-05	7e-05	7e-05	7e-05	0
1e+12	0.59978	0.60003	0.60038	0.00025131	0.5997	0.59993	0.60028	0.00025173	-0.00016	-0.0001075	-8e-05	3.594e-05
5e+12	0.59998	0.6002	0.60034	0.00016132	0.59867	0.59906	0.59925	0.00026458	-0.00131	-0.0011425	-0.00094	0.00015262
1e+13	0.59985	0.59996	0.60003	7.9373e-05	0.59766	0.5979	0.59813	0.00019908	-0.00228	-0.00206	-0.00187	0.00016951

Device Test: 19.8 CURRENT|EA//5/5/0/0/5/500kHz//@EA_IB





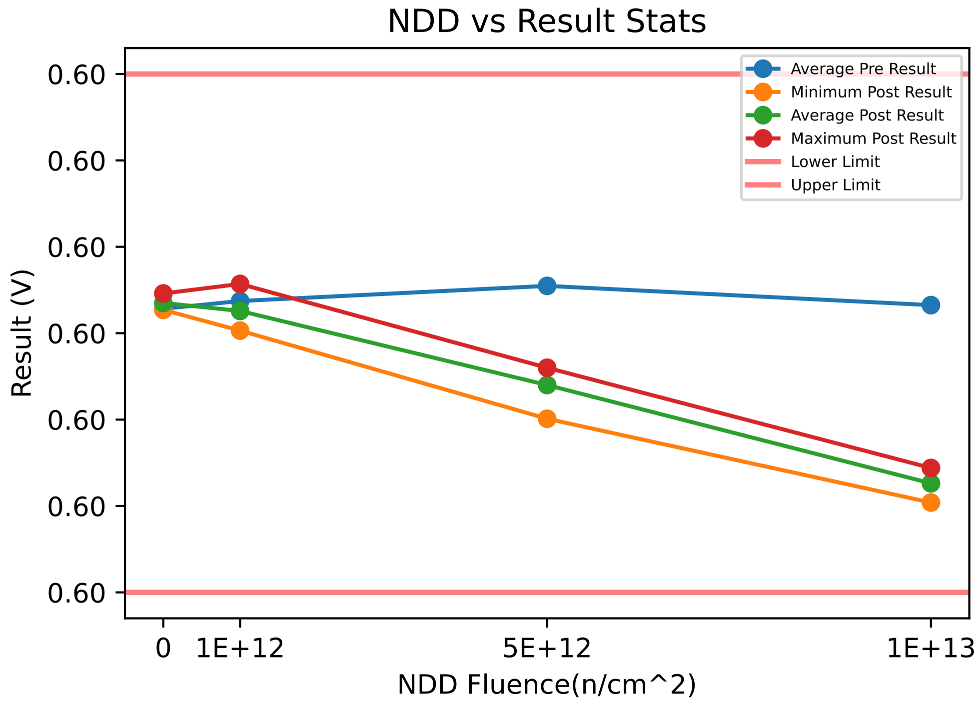
Test Results (Upper Limit = 25.0 (nA))

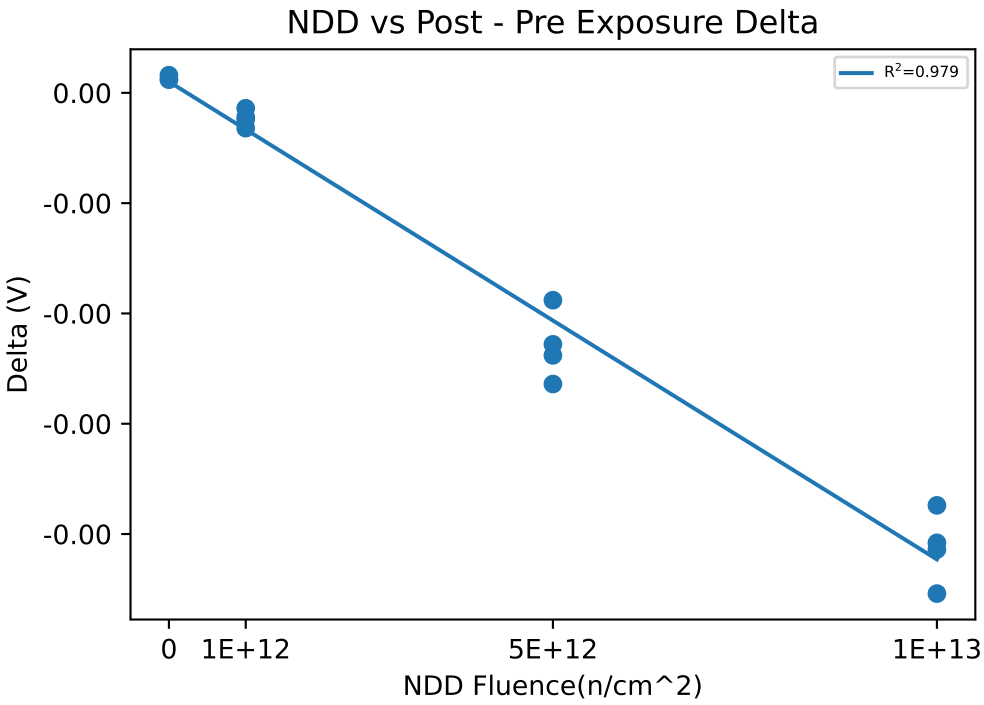
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.5997	-0.0318	-0.6315
2	1e+12	NDD	-0.3074	0.0703	0.3777
3	1e+12	NDD	-0.38	1.0365	1.4165
4	1e+12	NDD	-0.3461	0.1803	0.5264
5	5e+12	NDD	-0.713	0.2826	0.9956
6	5e+12	NDD	-0.408	1.0926	1.5006
7	5e+12	NDD	-0.2587	0.0587	0.3174
8	5e+12	NDD	-0.4696	0.1265	0.5961
9	1e+13	NDD	-0.3082	1.1488	1.457
10	1e+13	NDD	0.0504	-0.2064	-0.2568
11	1e+13	NDD	-0.4447	-0.142	0.3027
12	1e+13	NDD	-0.3362	1.1644	1.5006
13	0	CORRELATION	0.3719	-0.3748	-0.7467
14	0	CORRELATION	-0.3136	-0.4542	-0.1406
15	0	CORRELATION	-0.3175	1.3296	1.6471

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3175	-0.0864	0.3719	0.3969	-0.4542	0.16687	1.3296	1.0077	-0.7467	0.25327	1.6471	1.2446
1e+12	-0.38	-0.10845	0.5997	0.47303	-0.0318	0.31382	1.0365	0.48951	-0.6315	0.42228	1.4165	0.839
5e+12	-0.713	-0.46232	-0.2587	0.18913	0.0587	0.3901	1.0926	0.47762	0.3174	0.85242	1.5006	0.514
1e+13	-0.4447	-0.25967	0.0504	0.21494	-0.2064	0.4912	1.1644	0.76881	-0.2568	0.75088	1.5006	0.8712

Device Test: 19.81 VOLTAGE|VREF//12/12/0/1000/5/1MHz//@VREF_25C





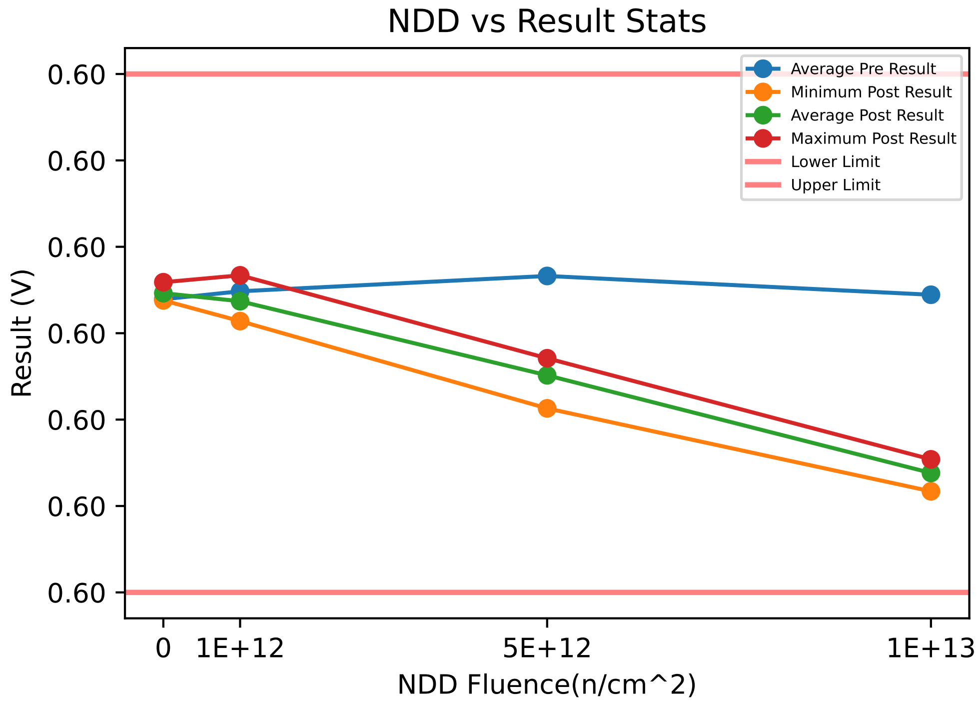
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

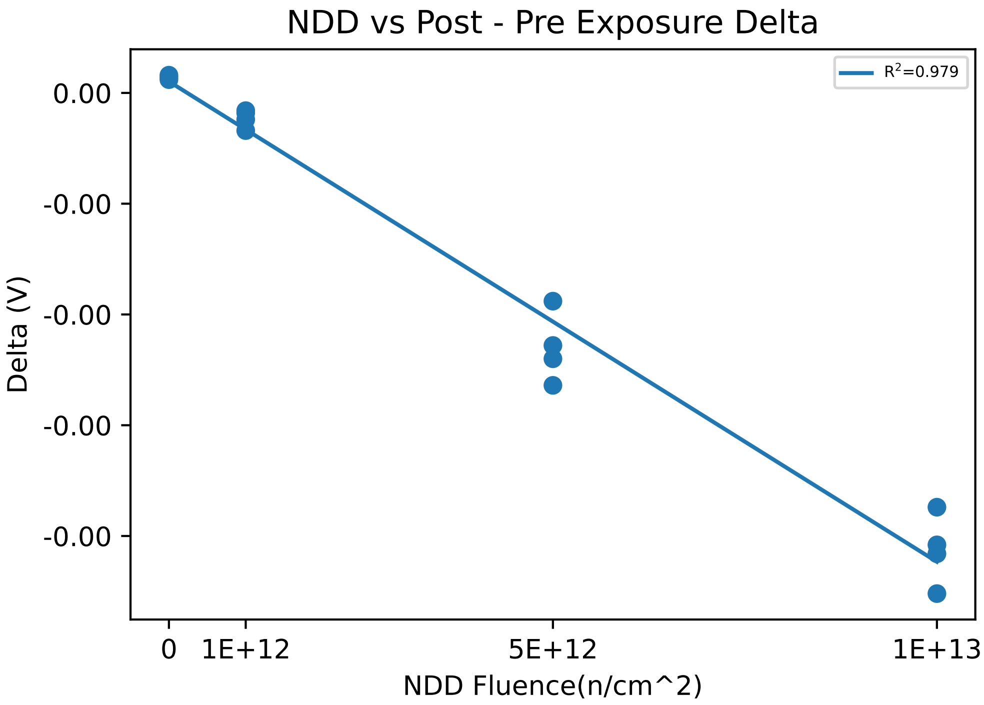
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6001	0.60003	-7e-05
2	1e+12	NDD	0.60035	0.60024	-0.00011
3	1e+12	NDD	0.60035	0.60019	-0.00016
4	1e+12	NDD	0.60069	0.60057	-0.00012
5	5e+12	NDD	0.60063	0.59944	-0.00119
6	5e+12	NDD	0.60069	0.59955	-0.00114
7	5e+12	NDD	0.60054	0.5996	-0.00094
8	5e+12	NDD	0.60033	0.59901	-0.00132
9	1e+13	NDD	0.60044	0.59837	-0.00207
10	1e+13	NDD	0.60024	0.5982	-0.00204
11	1e+13	NDD	0.60031	0.59844	-0.00187
12	1e+13	NDD	0.60031	0.59804	-0.00227
13	0	CORRELATION	0.60019	0.60027	8e-05
14	0	CORRELATION	0.60026	0.60032	6e-05
15	0	CORRELATION	0.6004	0.60046	6e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60019	0.60028	0.6004	0.00010693	0.60027	0.60035	0.60046	9.8489e-05	6e-05	6.6667e-05	8e-05	1.1547e-05
1e+12	0.6001	0.60037	0.60069	0.00024226	0.60003	0.60026	0.60057	0.00022677	-0.00016	-0.000115	-7e-05	3.6968e-05
5e+12	0.60033	0.60055	0.60069	0.00015756	0.59901	0.5994	0.5996	0.00026845	-0.00132	-0.0011475	-0.00094	0.00015777
1e+13	0.60024	0.60032	0.60044	8.3467e-05	0.59804	0.59826	0.59844	0.00017933	-0.00227	-0.0020625	-0.00187	0.00016399

Device Test: 19.83 VOLTAGE|VREF//14/14/0/1000/5/1MHz//@VREF_25C





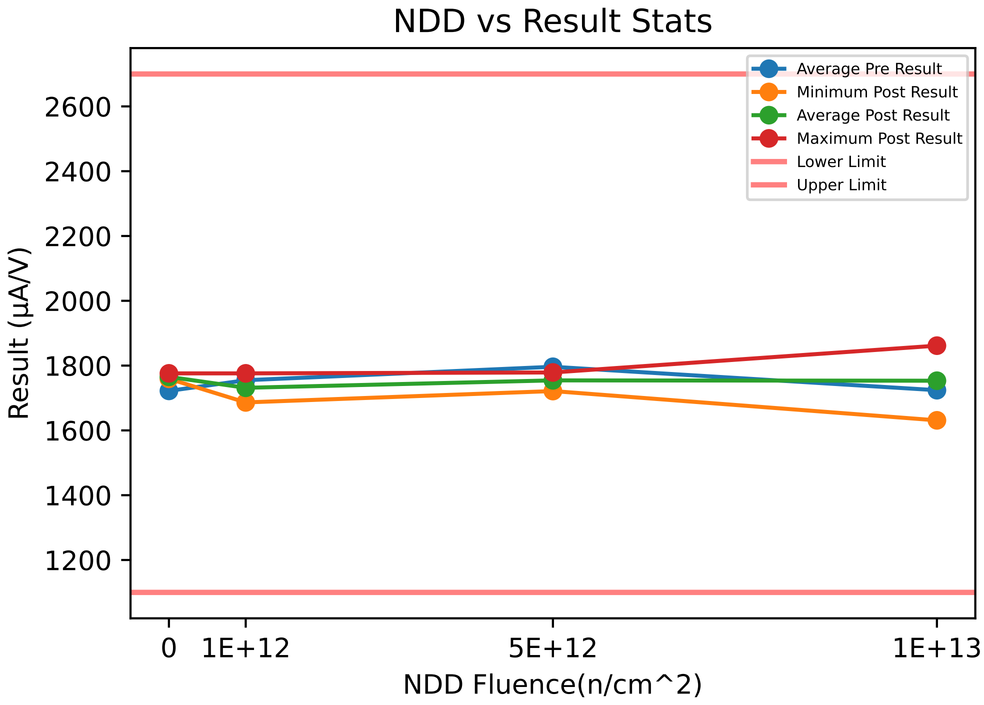
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

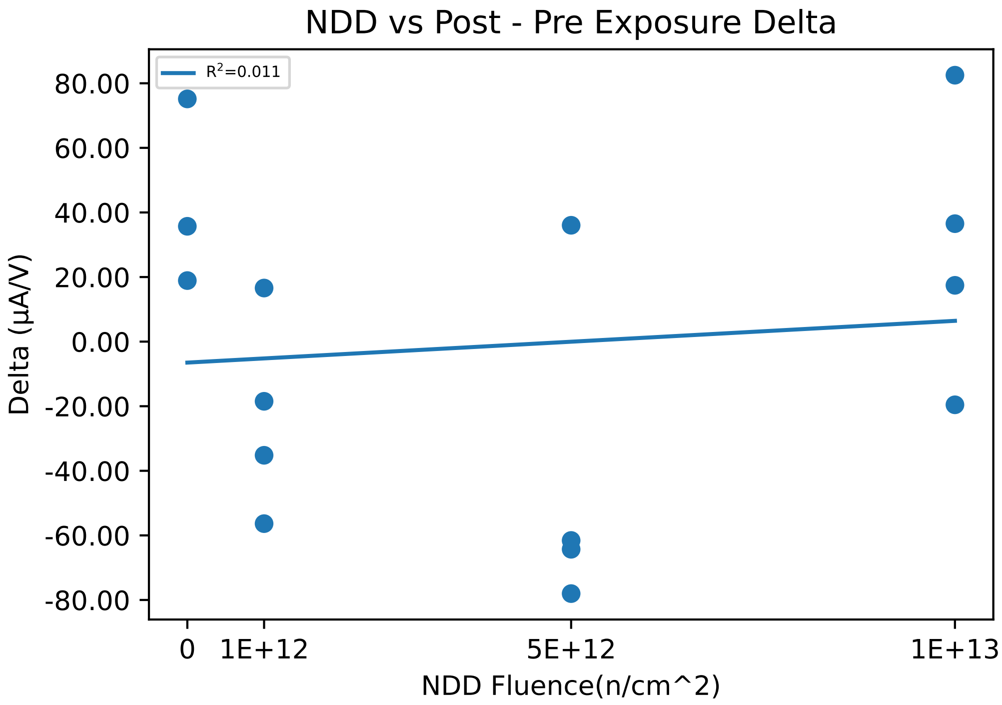
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.60022	0.60014	-8e-05
2	1e+12	NDD	0.60046	0.60037	-9e-05
3	1e+12	NDD	0.60047	0.6003	-0.00017
4	1e+12	NDD	0.60079	0.60067	-0.00012
5	5e+12	NDD	0.60074	0.59954	-0.0012
6	5e+12	NDD	0.60081	0.59967	-0.00114
7	5e+12	NDD	0.60065	0.59971	-0.00094
8	5e+12	NDD	0.60045	0.59913	-0.00132
9	1e+13	NDD	0.60058	0.5985	-0.00208
10	1e+13	NDD	0.60036	0.59832	-0.00204
11	1e+13	NDD	0.60041	0.59854	-0.00187
12	1e+13	NDD	0.60043	0.59817	-0.00226
13	0	CORRELATION	0.6003	0.60038	8e-05
14	0	CORRELATION	0.60036	0.60042	6e-05
15	0	CORRELATION	0.60052	0.60059	7e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6003	0.60039	0.60052	0.00011372	0.60038	0.60046	0.60059	0.0001115	6e-05	7e-05	8e-05	1e-05
1e+12	0.60022	0.60048	0.60079	0.00023388	0.60014	0.60037	0.60067	0.00022196	-0.00017	-0.000115	-8e-05	4.0415e-05
5e+12	0.60045	0.60066	0.60081	0.00015607	0.59913	0.59951	0.59971	0.00026513	-0.00132	-0.00115	-0.00094	0.00015875
1e+13	0.60036	0.60045	0.60058	9.4692e-05	0.59817	0.59838	0.59854	0.00017095	-0.00226	-0.0020625	-0.00187	0.00016008

Device Test: 19.9 LEVEL|TRANSCONDUCTANCE//12/12/0/0/5/500kHz//@EA_GM





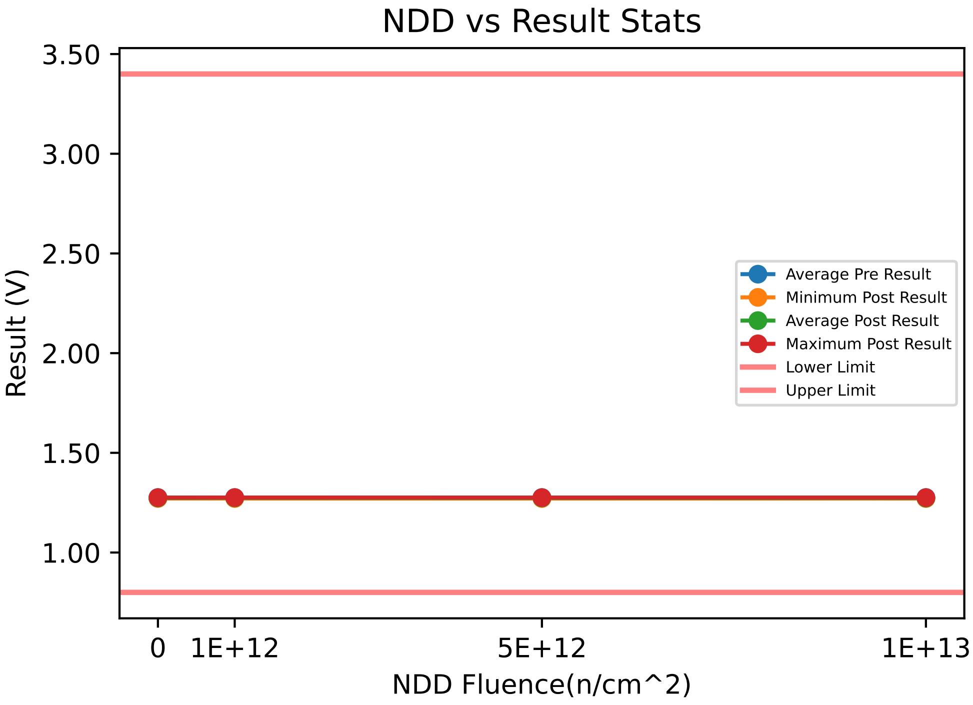
Test Results (Lower Limit = 1100.0,
Upper Limit = 2700.0 (μA/V))

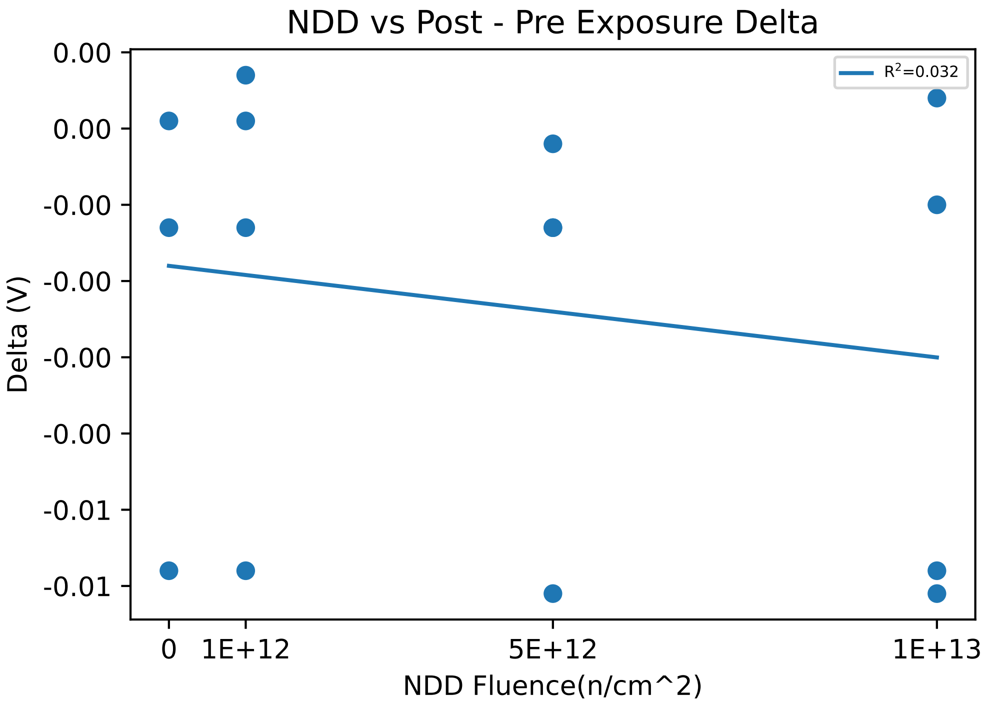
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1778.9	1760.5	-18.48
2	1e+12	NDD	1759.5	1703.1	-56.361
3	1e+12	NDD	1759.4	1776	16.595
4	1e+12	NDD	1721.5	1686.3	-35.196
5	5e+12	NDD	1840.4	1778.8	-61.572
6	5e+12	NDD	1840.3	1776	-64.299
7	5e+12	NDD	1819.4	1741.3	-78.026
8	5e+12	NDD	1685.4	1721.4	36.03
9	1e+13	NDD	1650.6	1631	-19.561
10	1e+13	NDD	1667.8	1704.3	36.526
11	1e+13	NDD	1779	1861.5	82.501
12	1e+13	NDD	1799	1816.4	17.431
13	0	CORRELATION	1685.3	1760.5	75.158
14	0	CORRELATION	1740.3	1759.3	18.906
15	0	CORRELATION	1740.3	1776	35.713

Test Statistics (μA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1685.3	1722	1740.3	31.768	1759.3	1765.2	1776	9.3529	18.906	43.259	75.158	28.875
1e+12	1721.5	1754.8	1778.9	24.029	1686.3	1731.5	1776	43.458	-56.361	-23.36	16.595	30.819
5e+12	1685.4	1796.4	1840.4	74.64	1721.4	1754.4	1778.8	27.818	-78.026	-41.967	36.03	52.494
1e+13	1650.6	1724.1	1799	75.717	1631	1753.3	1861.5	104.95	-19.561	29.224	82.501	42.469

Device Test: 20.1 LEVEL|LOW_LEVEL/SYNC/4.5/4.5/0/0/4.5/500kHz//@SYNC_VIL_TH_LOW_4P5





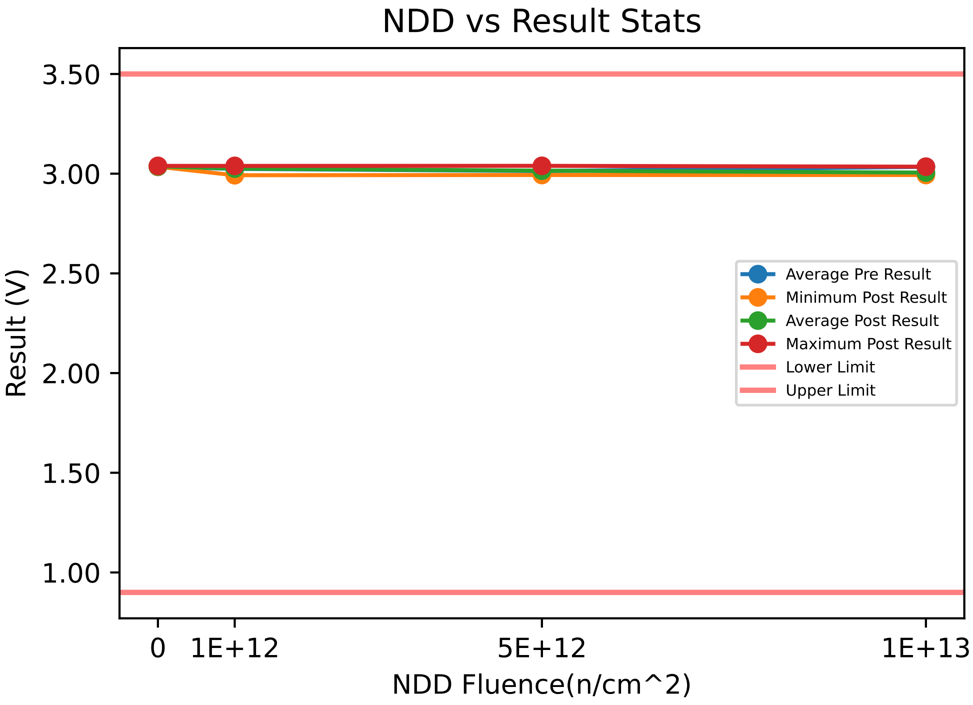
Test Results (Lower Limit = 0.8, Upper Limit = 3.4 (V))

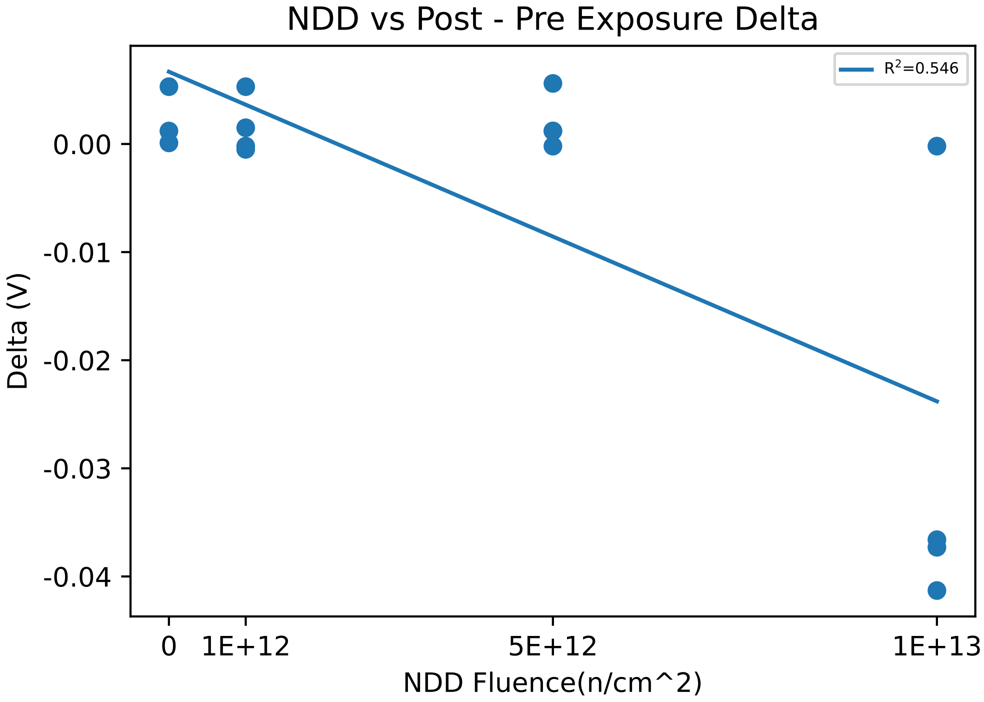
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2753	1.2754	0.0001
2	1e+12	NDD	1.2757	1.2744	-0.0013
3	1e+12	NDD	1.2765	1.2707	-0.0058
4	1e+12	NDD	1.275	1.2757	0.0007
5	5e+12	NDD	1.2757	1.2744	-0.0013
6	5e+12	NDD	1.2768	1.2707	-0.0061
7	5e+12	NDD	1.2756	1.2754	-0.0002
8	5e+12	NDD	1.2757	1.2744	-0.0013
9	1e+13	NDD	1.2768	1.2707	-0.0061
10	1e+13	NDD	1.275	1.2754	0.0004
11	1e+13	NDD	1.2757	1.2747	-0.001
12	1e+13	NDD	1.2765	1.2707	-0.0058
13	0	CORRELATION	1.2753	1.2754	0.0001
14	0	CORRELATION	1.2757	1.2744	-0.0013
15	0	CORRELATION	1.2768	1.271	-0.0058

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2753	1.2759	1.2768	0.00077675	1.271	1.2736	1.2754	0.0023065	-0.0058	-0.0023333	0.0001	0.0030827
1e+12	1.275	1.2756	1.2765	0.00065	1.2707	1.274	1.2757	0.0023014	-0.0058	-0.001575	0.0007	0.0029387
5e+12	1.2756	1.2759	1.2768	0.00056862	1.2707	1.2737	1.2754	0.002071	-0.0061	-0.002225	-0.0002	0.0026349
1e+13	1.275	1.276	1.2768	0.0008124	1.2707	1.2729	1.2754	0.0025277	-0.0061	-0.003125	0.0004	0.003314

Device Test: 20.10 LEVEL|HIGH_LEVEL/SYNC/5.5/5.5/0/0/5.5/500kHz//@SYNC_VIH_TH_LOW_5P5





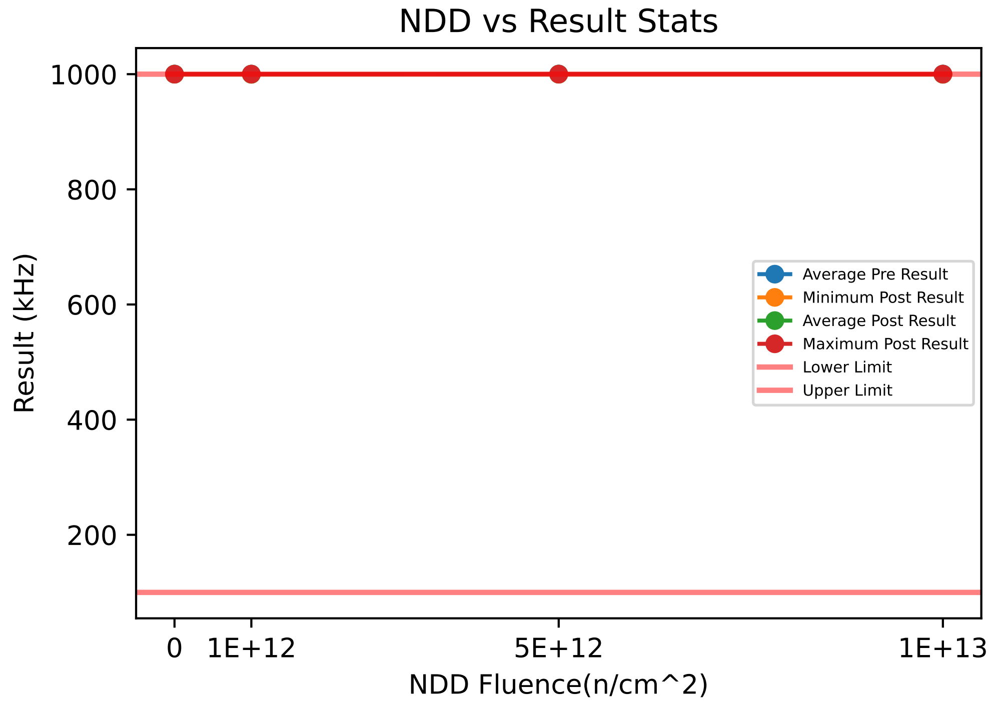
Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

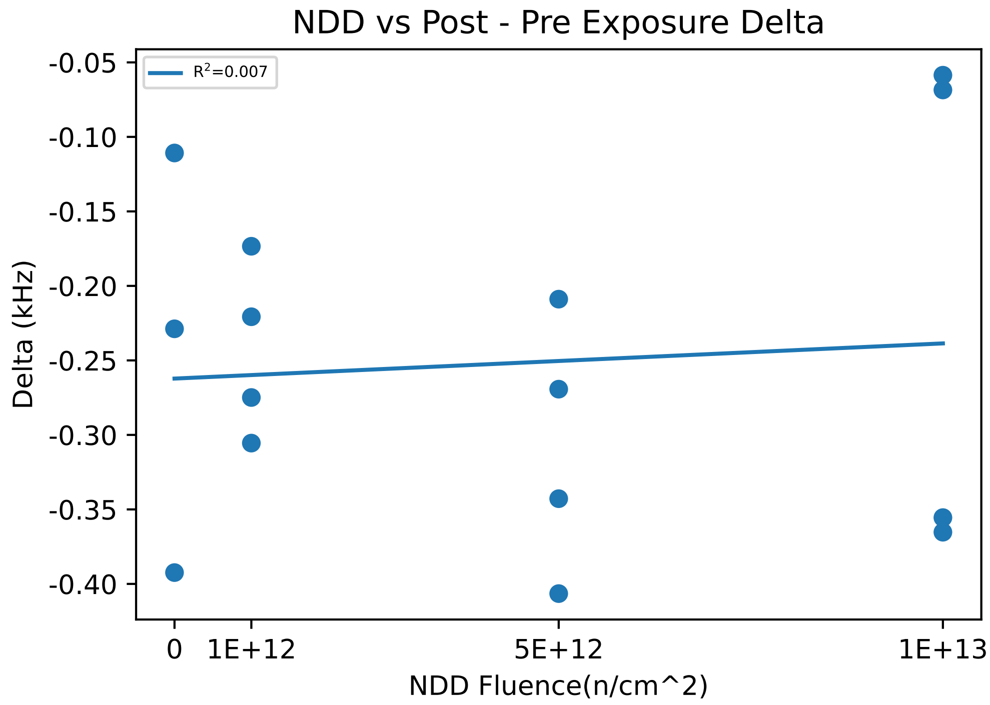
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.035	3.0348	-0.0002
2	1e+12	NDD	3.0347	3.0362	0.0015
3	1e+12	NDD	3.0338	3.0391	0.0053
4	1e+12	NDD	2.9928	2.9923	-0.0005
5	5e+12	NDD	2.9922	2.9934	0.0012
6	5e+12	NDD	3.0338	3.0394	0.0056
7	5e+12	NDD	3.035	3.0348	-0.0002
8	5e+12	NDD	2.9922	2.9934	0.0012
9	1e+13	NDD	3.0338	2.9972	-0.0366
10	1e+13	NDD	3.0353	3.0351	-0.0002
11	1e+13	NDD	3.0347	2.9934	-0.0413
12	1e+13	NDD	3.0338	2.9965	-0.0373
13	0	CORRELATION	3.0347	3.0348	0.0001
14	0	CORRELATION	3.0347	3.0359	0.0012
15	0	CORRELATION	3.0338	3.0391	0.0053

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0338	3.0344	3.0347	0.00051962	3.0348	3.0366	3.0391	0.0022338	0.0001	0.0022	0.0053	0.0027404
1e+12	2.9928	3.0241	3.035	0.020856	2.9923	3.0256	3.0391	0.022272	-0.0005	0.001525	0.0053	0.0026663
5e+12	2.9922	3.0133	3.035	0.024369	2.9934	3.0152	3.0394	0.0253	-0.0002	0.00195	0.0056	0.0025212
1e+13	3.0338	3.0344	3.0353	0.00073485	2.9934	3.0055	3.0351	0.019769	-0.0413	-0.02885	-0.0002	0.019212

Device Test: 20.100 LEVEL|FREQ/SYNC/12/12/0/1000/5/1MHz//@FREQ_SYNC_EXT





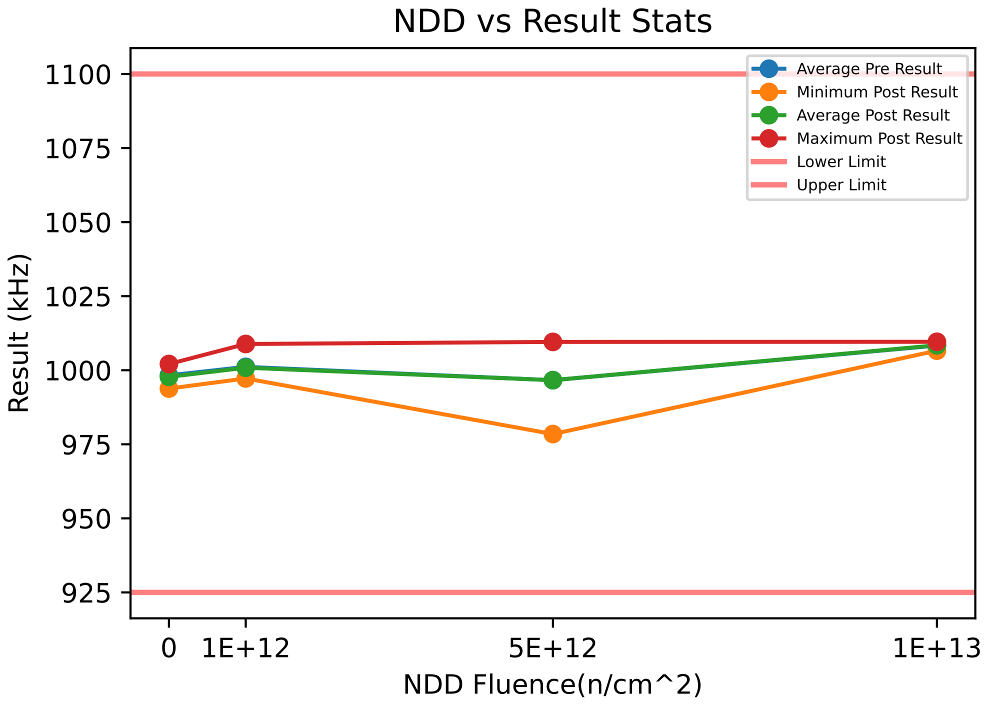
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000.1	999.89	-0.1734
2	1e+12	NDD	1000.1	999.88	-0.2207
3	1e+12	NDD	1000.4	1000.1	-0.2749
4	1e+12	NDD	1000	999.74	-0.3055
5	5e+12	NDD	1000.3	1000	-0.2693
6	5e+12	NDD	1000.3	999.91	-0.4065
7	5e+12	NDD	1000.2	999.89	-0.3428
8	5e+12	NDD	1000.3	1000.1	-0.2089
9	1e+13	NDD	1000.1	1000.1	-0.0586
10	1e+13	NDD	1000.1	999.73	-0.3653
11	1e+13	NDD	1000.3	999.92	-0.3555
12	1e+13	NDD	1000.2	1000.1	-0.0685
13	0	CORRELATION	1000	999.92	-0.1108
14	0	CORRELATION	1000.2	1000	-0.2288
15	0	CORRELATION	1000.3	999.92	-0.3924

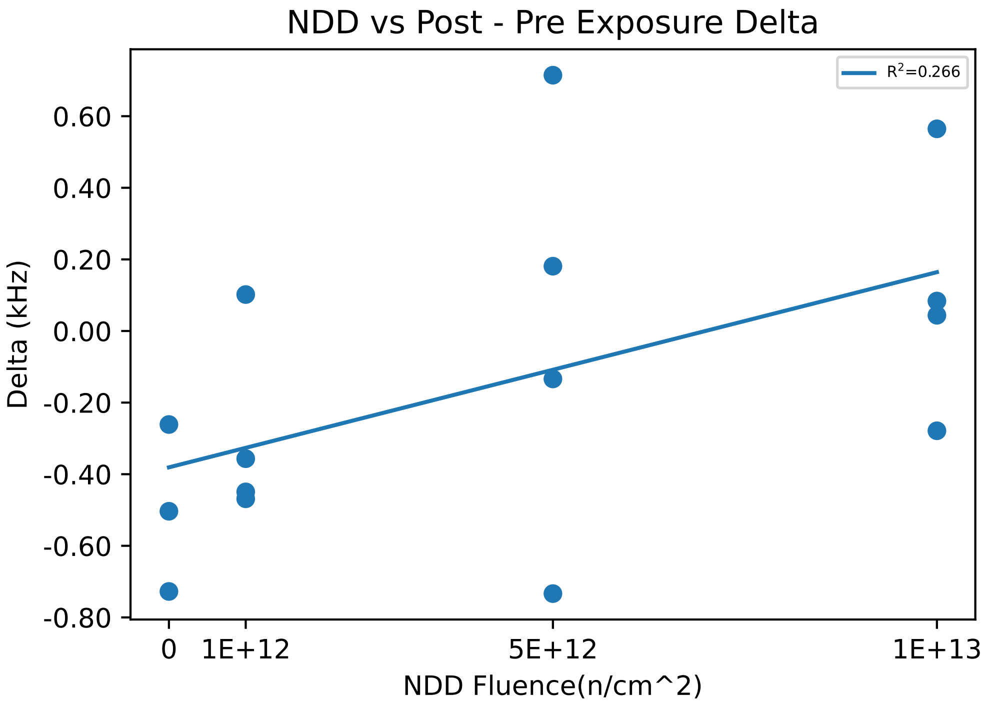
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000	1000.2	1000.3	0.14726	999.92	999.95	1000	0.057419	-0.3924	-0.244	-0.1108	0.14141
1e+12	1000	1000.1	1000.4	0.14678	999.74	999.9	1000.1	0.14284	-0.3055	-0.24362	-0.1734	0.058491
5e+12	1000.2	1000.3	1000.3	0.038871	999.89	999.97	1000.1	0.086588	-0.4065	-0.30687	-0.2089	0.086075
1e+13	1000.1	1000.2	1000.3	0.075655	999.73	999.96	1000.1	0.1734	-0.3653	-0.21197	-0.0586	0.17148

Device Test: 20.101 LEVEL|FREQ/RT/14/14/0/1000/5/1MHz//@FSW_EXT_RT_D



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

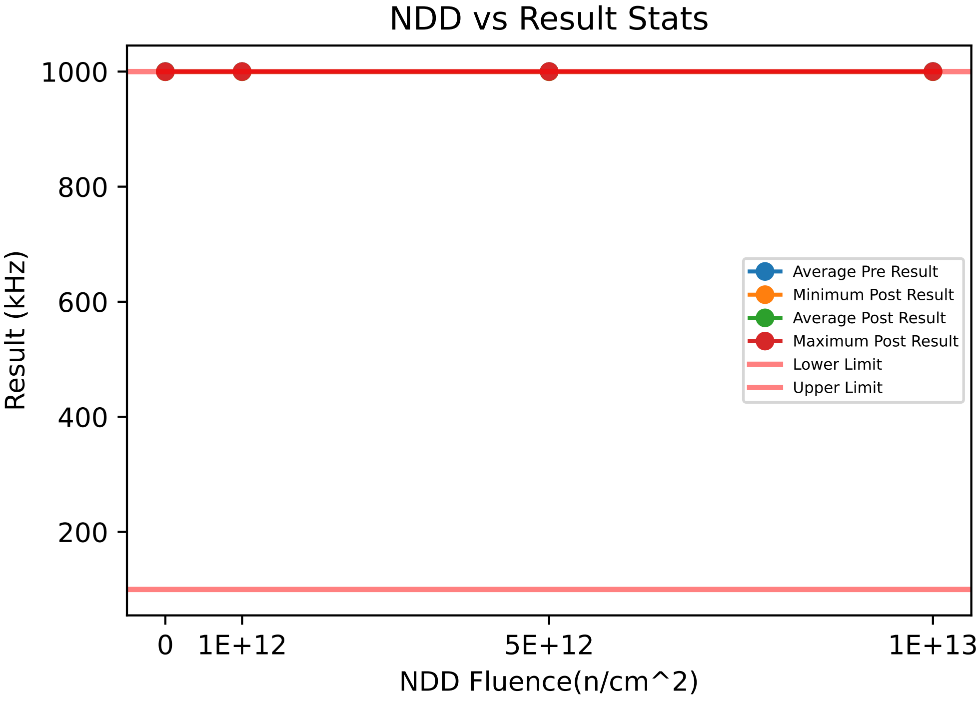
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

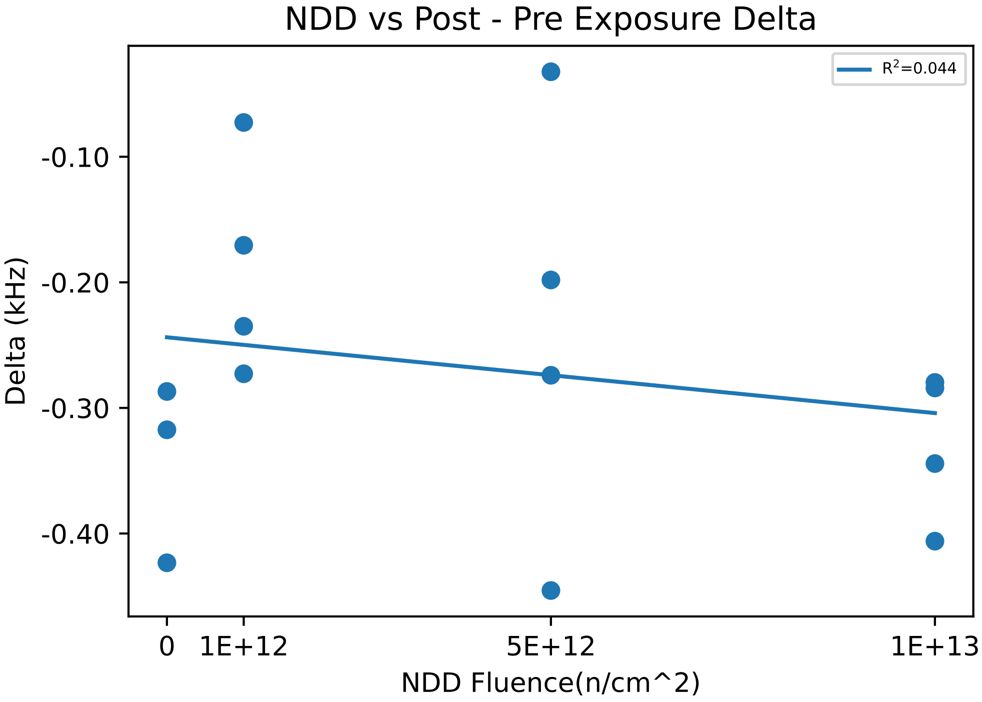
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1009.3	1008.9	-0.4494
2	1e+12	NDD	997.69	997.23	-0.4687
3	1e+12	NDD	997.33	997.43	0.1018
4	1e+12	NDD	1000.2	999.87	-0.3567
5	5e+12	NDD	978.58	978.45	-0.1339
6	5e+12	NDD	995.53	995.71	0.181
7	5e+12	NDD	1002.1	1002.9	0.7145
8	5e+12	NDD	1010.3	1009.6	-0.7335
9	1e+13	NDD	1009	1009.6	0.5647
10	1e+13	NDD	1009	1009.1	0.0837
11	1e+13	NDD	1008.7	1008.5	-0.2787
12	1e+13	NDD	1006.6	1006.6	0.0439
13	0	CORRELATION	997.9	997.4	-0.5035
14	0	CORRELATION	1002.4	1002.1	-0.2612
15	0	CORRELATION	994.53	993.8	-0.7275

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.53	998.26	1002.4	3.9247	993.8	997.76	1002.1	4.1575	-0.7275	-0.4974	-0.2612	0.23321
1e+12	997.33	1001.1	1009.3	5.596	997.23	1000.8	1008.9	5.4749	-0.4687	-0.29325	0.1018	0.26787
5e+12	978.58	996.64	1010.3	13.465	978.45	996.64	1009.6	13.382	-0.7335	0.007025	0.7145	0.60526
1e+13	1006.6	1008.3	1009	1.1827	1006.6	1008.4	1009.6	1.3014	-0.2787	0.1034	0.5647	0.34772

Device Test: 20.102 LEVEL|FREQ/SYNC/14/14/0/1000/5/1MHz//@FREQ_SYNC_EXT





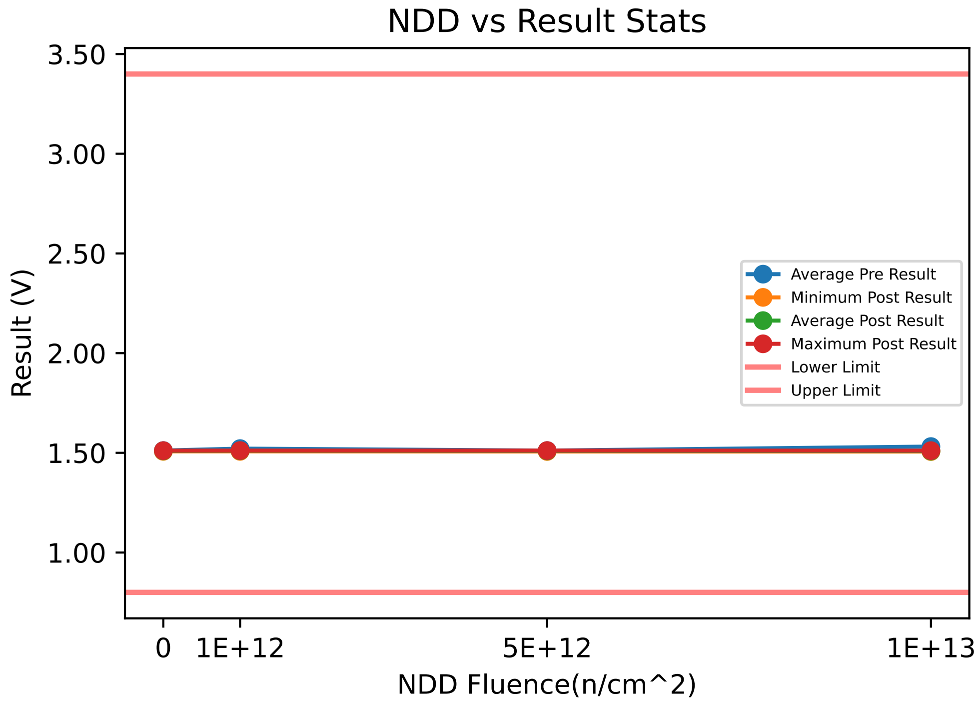
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

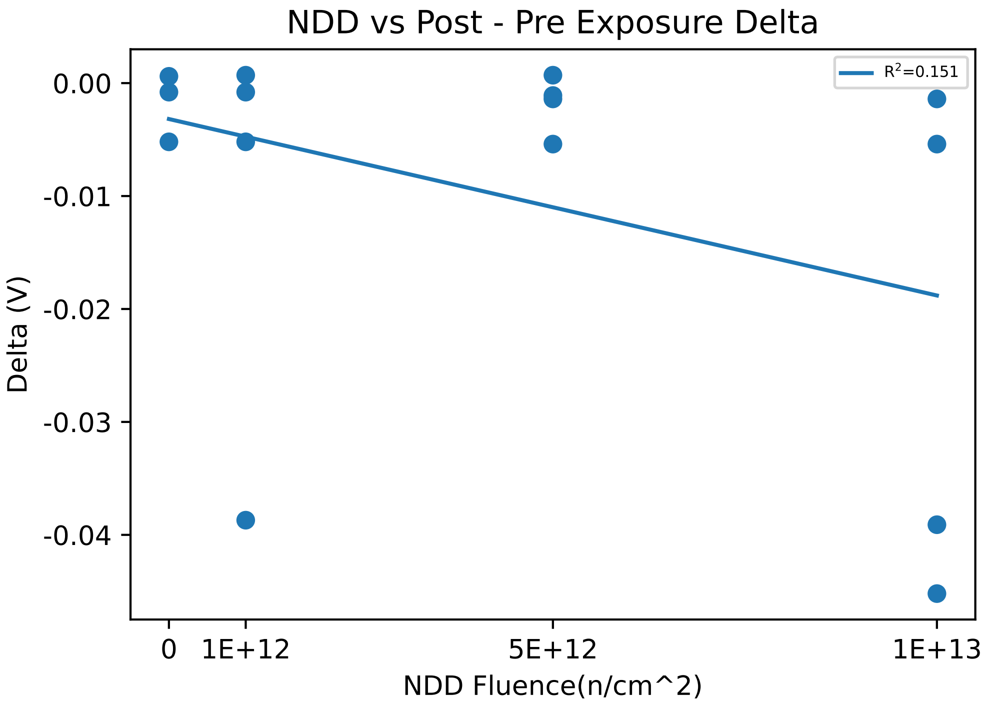
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000	999.77	-0.2728
2	1e+12	NDD	1000.1	1000	-0.0727
3	1e+12	NDD	1000.2	999.94	-0.235
4	1e+12	NDD	1000	999.86	-0.1705
5	5e+12	NDD	1000.1	999.93	-0.1981
6	5e+12	NDD	1000.1	1000.1	-0.0323
7	5e+12	NDD	1000.2	999.76	-0.4454
8	5e+12	NDD	1000.2	999.89	-0.274
9	1e+13	NDD	1000.3	1000	-0.2841
10	1e+13	NDD	1000.2	999.86	-0.3443
11	1e+13	NDD	1000.3	999.87	-0.4061
12	1e+13	NDD	1000.2	999.91	-0.2797
13	0	CORRELATION	1000.2	999.86	-0.3174
14	0	CORRELATION	1000.1	999.85	-0.2869
15	0	CORRELATION	1000.3	999.87	-0.4233

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000.1	1000.2	1000.3	0.084342	999.85	999.86	999.87	0.013041	-0.4233	-0.34253	-0.2869	0.071589
1e+12	1000	1000.1	1000.2	0.066288	999.77	999.9	1000	0.10785	-0.2728	-0.18775	-0.0727	0.08756
5e+12	1000.1	1000.2	1000.2	0.04009	999.76	999.92	1000.1	0.13292	-0.4454	-0.23745	-0.0323	0.17148
1e+13	1000.2	1000.2	1000.3	0.058915	999.86	999.92	1000	0.078237	-0.4061	-0.32855	-0.2797	0.05951

Device Test: 20.11 LEVEL|LOW_LEVEL/SYNC/6/6/0/0/5.5/500kHz//@SYNC_VIL_TH_HIGH_5P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

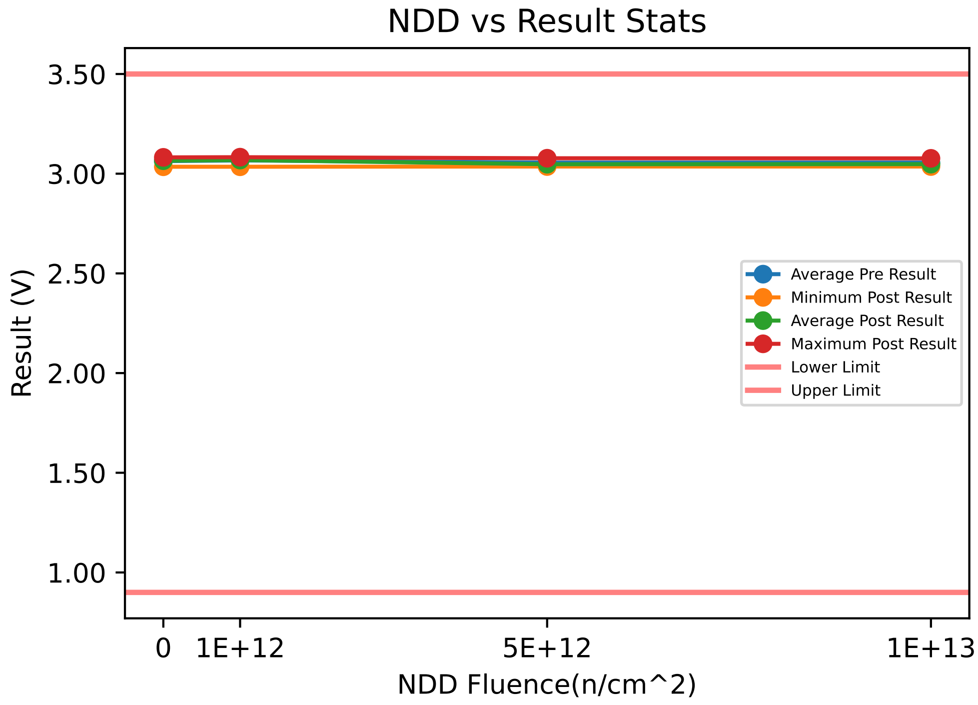
Test Results (Lower Limit = 0.8,
Upper Limit = 3.4 (V))

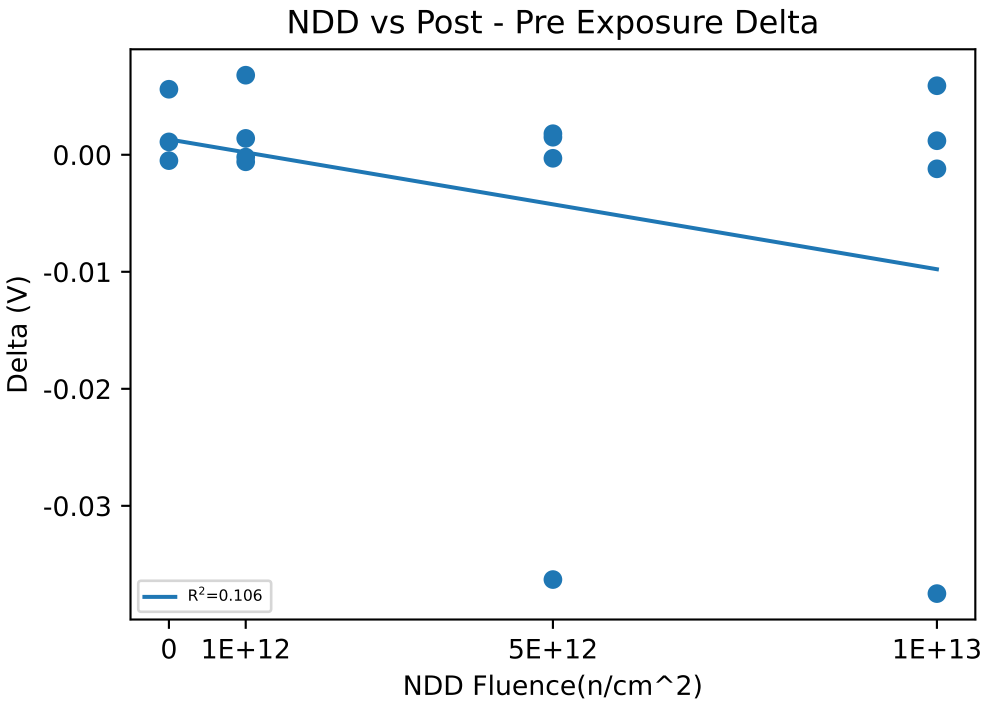
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5501	1.5114	-0.0387
2	1e+12	NDD	1.5115	1.5107	-0.0008
3	1e+12	NDD	1.5126	1.5074	-0.0052
4	1e+12	NDD	1.5107	1.5114	0.0007
5	5e+12	NDD	1.5115	1.5101	-0.0014
6	5e+12	NDD	1.5122	1.5068	-0.0054
7	5e+12	NDD	1.5107	1.5114	0.0007
8	5e+12	NDD	1.5112	1.5101	-0.0011
9	1e+13	NDD	1.5122	1.5068	-0.0054
10	1e+13	NDD	1.5501	1.511	-0.0391
11	1e+13	NDD	1.5118	1.5104	-0.0014
12	1e+13	NDD	1.5516	1.5064	-0.0452
13	0	CORRELATION	1.5104	1.511	0.0006
14	0	CORRELATION	1.5115	1.5107	-0.0008
15	0	CORRELATION	1.5126	1.5074	-0.0052

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5104	1.5115	1.5126	0.0011	1.5074	1.5097	1.511	0.0019975	-0.0052	-0.0018	0.0006	0.0030265
1e+12	1.5107	1.5212	1.5501	0.019266	1.5074	1.5102	1.5114	0.001912	-0.0387	-0.011	0.0007	0.018636
5e+12	1.5107	1.5114	1.5122	0.00062716	1.5068	1.5096	1.5114	0.0019647	-0.0054	-0.0018	0.0007	0.0025729
1e+13	1.5118	1.5314	1.5516	0.022439	1.5064	1.5086	1.511	0.0023854	-0.0452	-0.022775	-0.0014	0.02257

Device Test: 20.12 LEVEL|HIGH_LEVEL/SYNC/6/6/0/0/5.5/500kHz//@SYNC_VIH_TH_HIGH_5P5





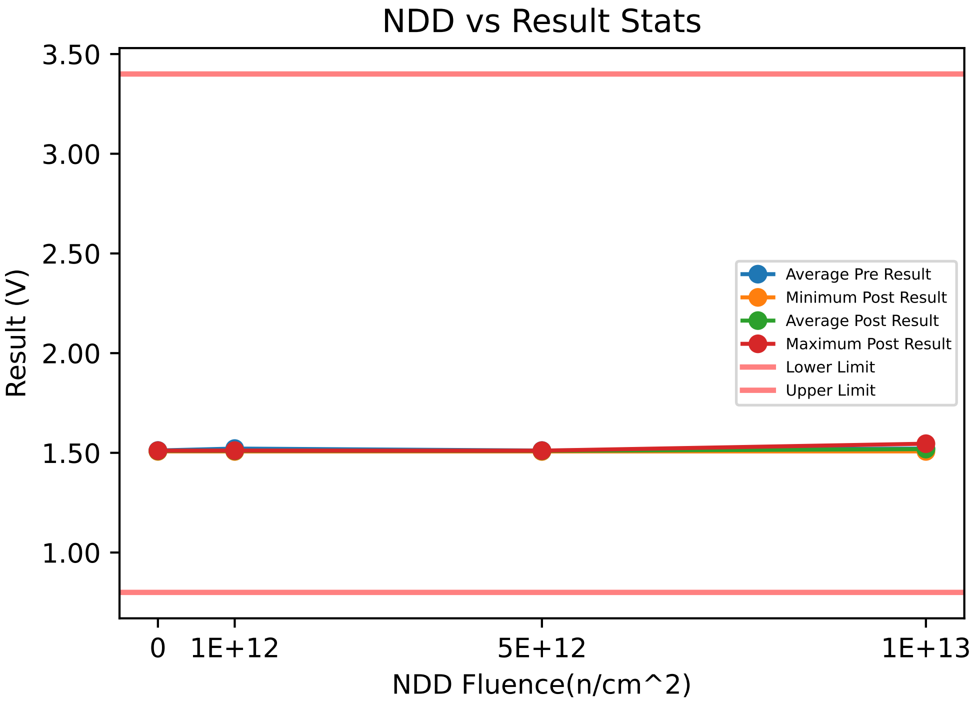
Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

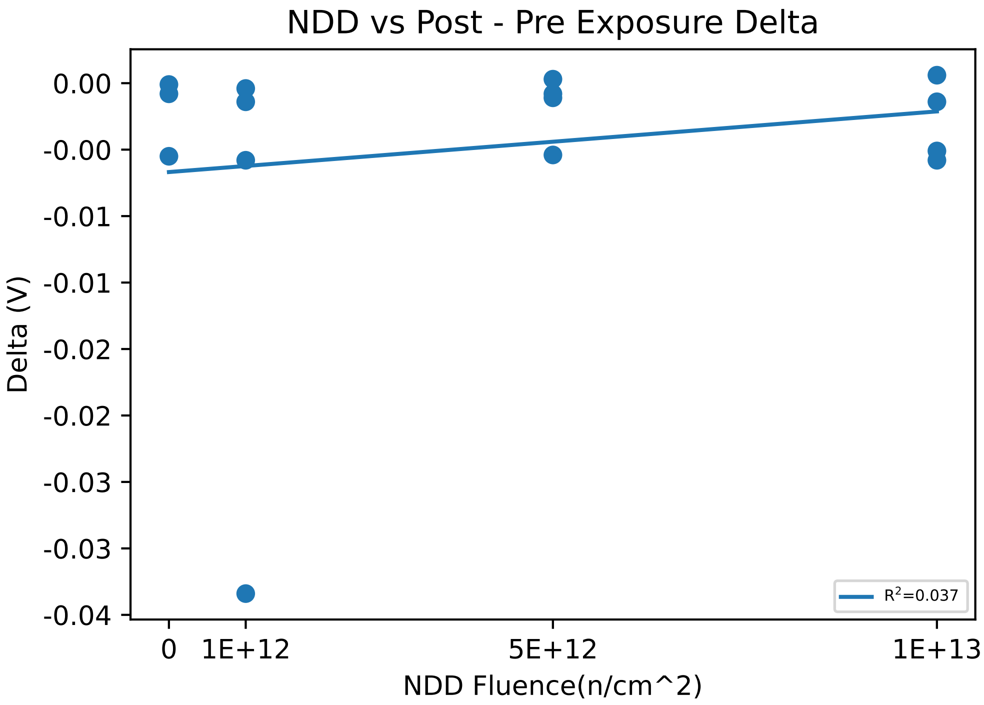
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.0778	3.0772	-0.0006
2	1e+12	NDD	3.0772	3.0786	0.0014
3	1e+12	NDD	3.076	3.0828	0.0068
4	1e+12	NDD	3.035	3.0348	-0.0002
5	5e+12	NDD	3.0344	3.0362	0.0018
6	5e+12	NDD	3.0763	3.04	-0.0363
7	5e+12	NDD	3.0778	3.0775	-0.0003
8	5e+12	NDD	3.0344	3.0359	0.0015
9	1e+13	NDD	3.0335	3.0394	0.0059
10	1e+13	NDD	3.0781	3.0769	-0.0012
11	1e+13	NDD	3.0347	3.0359	0.0012
12	1e+13	NDD	3.0766	3.0391	-0.0375
13	0	CORRELATION	3.0353	3.0348	-0.0005
14	0	CORRELATION	3.0772	3.0783	0.0011
15	0	CORRELATION	3.0763	3.0819	0.0056

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0353	3.0629	3.0772	0.023935	3.0348	3.065	3.0819	0.026216	-0.0005	0.0020667	0.0056	0.0031628
1e+12	3.035	3.0665	3.0778	0.021013	3.0348	3.0684	3.0828	0.022493	-0.0006	0.00185	0.0068	0.0034113
5e+12	3.0344	3.0557	3.0778	0.024632	3.0359	3.0474	3.0775	0.020153	-0.0363	-0.008325	0.0018	0.018673
1e+13	3.0335	3.0557	3.0781	0.024983	3.0359	3.0478	3.0769	0.019448	-0.0375	-0.0079	0.0059	0.019952

Device Test: 20.13 LEVEL|LOW_LEVEL/SYNC/12/12/0/0/5.5/500kHz//@SYNC_VIL_TH_HIGH_5P5





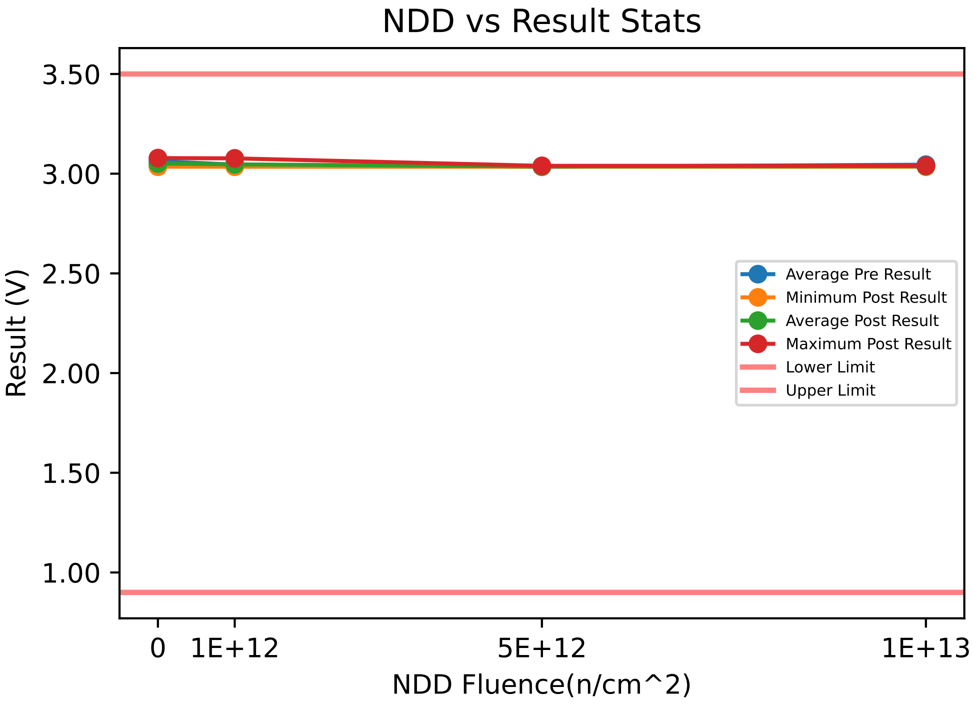
Test Results (Lower Limit = 0.8,
Upper Limit = 3.4 (V))

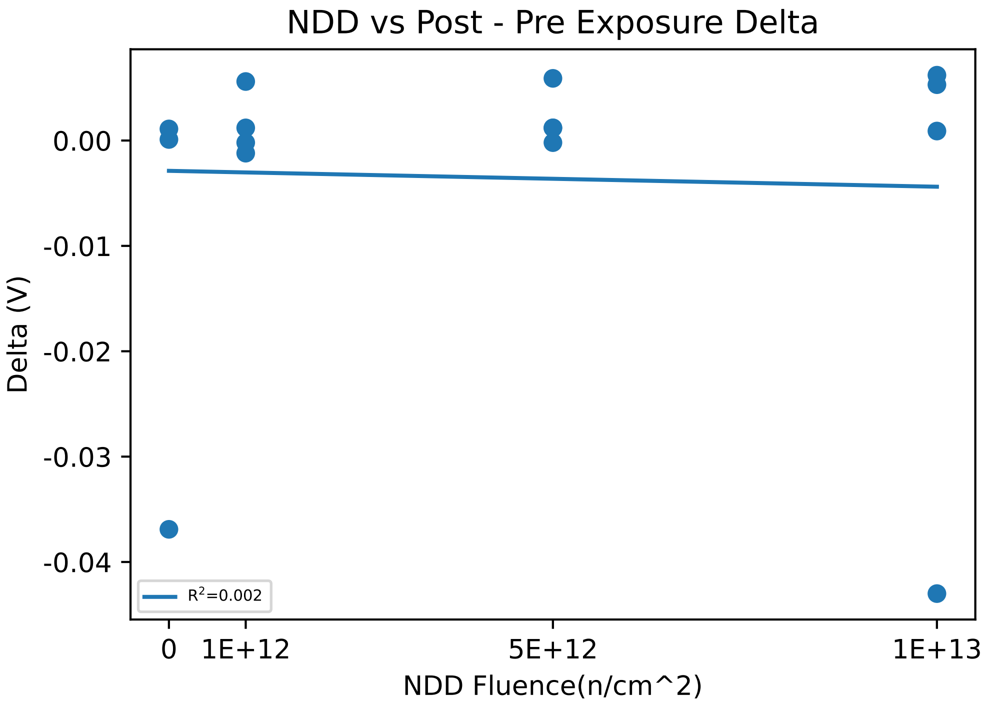
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5498	1.5114	-0.0384
2	1e+12	NDD	1.5118	1.5104	-0.0014
3	1e+12	NDD	1.5126	1.5068	-0.0058
4	1e+12	NDD	1.5114	1.511	-0.0004
5	5e+12	NDD	1.5115	1.5104	-0.0011
6	5e+12	NDD	1.5122	1.5068	-0.0054
7	5e+12	NDD	1.5107	1.511	0.0003
8	5e+12	NDD	1.5115	1.5107	-0.0008
9	1e+13	NDD	1.5122	1.5071	-0.0051
10	1e+13	NDD	1.5104	1.511	0.0006
11	1e+13	NDD	1.5118	1.5104	-0.0014
12	1e+13	NDD	1.5516	1.5458	-0.0058
13	0	CORRELATION	1.5111	1.511	-0.0001
14	0	CORRELATION	1.5115	1.5107	-0.0008
15	0	CORRELATION	1.5126	1.5071	-0.0055

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5111	1.5117	1.5126	0.00077675	1.5071	1.5096	1.511	0.0021703	-0.0055	-0.0021333	-0.0001	0.0029366
1e+12	1.5114	1.5214	1.5498	0.01894	1.5068	1.5099	1.5114	0.0021071	-0.0384	-0.0115	-0.0004	0.018086
5e+12	1.5107	1.5115	1.5122	0.00061305	1.5068	1.5097	1.511	0.0019653	-0.0054	-0.00175	0.0003	0.0025067
1e+13	1.5104	1.5215	1.5516	0.020082	1.5071	1.5186	1.5458	0.018231	-0.0058	-0.002925	0.0006	0.0030412

Device Test: 20.14 LEVEL|HIGH_LEVEL/SYNC/12/12/0/0/5.5/500kHz//@SYNC_VIH_TH_HIGH_5P5





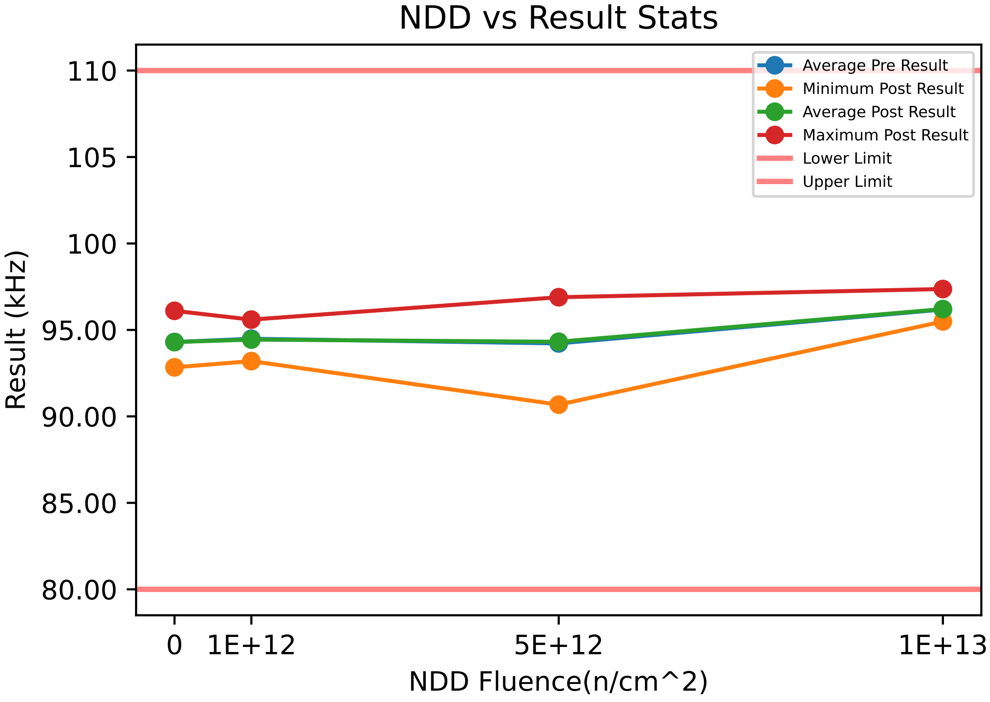
Test Results (Lower Limit = 0.9,
Upper Limit = 3.5 (V))

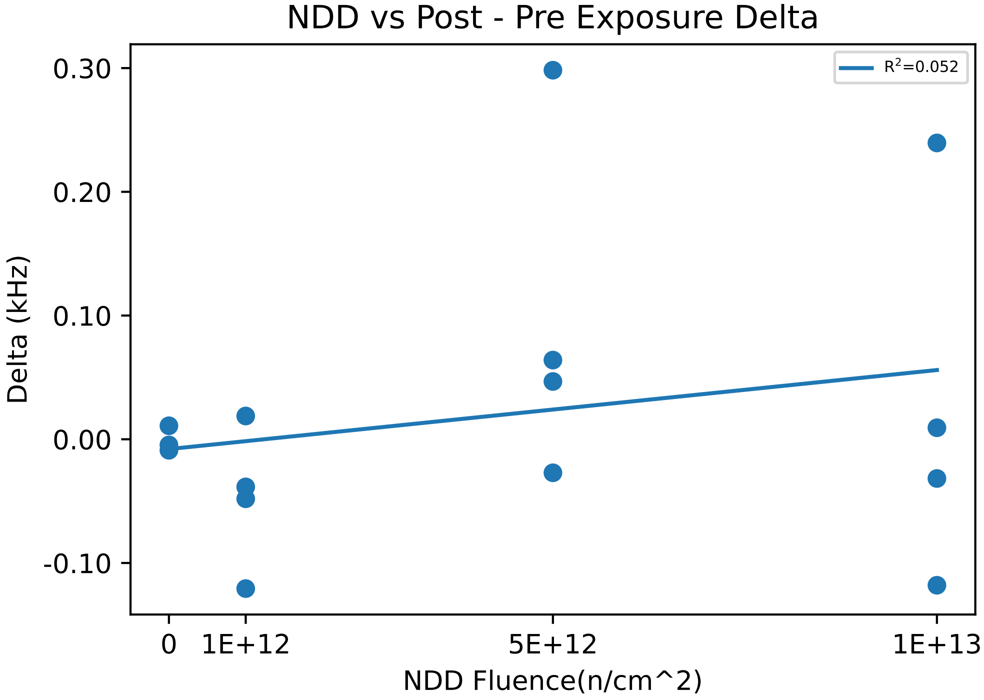
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.0781	3.0769	-0.0012
2	1e+12	NDD	3.0347	3.0359	0.0012
3	1e+12	NDD	3.0335	3.0391	0.0056
4	1e+12	NDD	3.035	3.0348	-0.0002
5	5e+12	NDD	3.0347	3.0359	0.0012
6	5e+12	NDD	3.0335	3.0394	0.0059
7	5e+12	NDD	3.035	3.0348	-0.0002
8	5e+12	NDD	3.035	3.0362	0.0012
9	1e+13	NDD	3.0338	3.04	0.0062
10	1e+13	NDD	3.0778	3.0348	-0.043
11	1e+13	NDD	3.035	3.0359	0.0009
12	1e+13	NDD	3.0341	3.0394	0.0053
13	0	CORRELATION	3.035	3.0351	0.0001
14	0	CORRELATION	3.0772	3.0783	0.0011
15	0	CORRELATION	3.0763	3.0394	-0.0369

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.035	3.0628	3.0772	0.024109	3.0351	3.0509	3.0783	0.023798	-0.0369	-0.0119	0.0011	0.021656
1e+12	3.0335	3.0453	3.0781	0.02186	3.0348	3.0467	3.0769	0.020232	-0.0012	0.00135	0.0056	0.0029994
5e+12	3.0335	3.0346	3.035	0.00071414	3.0348	3.0366	3.0394	0.0019772	-0.0002	0.002025	0.0059	0.0026663
1e+13	3.0338	3.0452	3.0778	0.021756	3.0348	3.0375	3.04	0.002563	-0.043	-0.00765	0.0062	0.02368

Device Test: 20.15 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/100kHz//@FSW_EXT_RT_A


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

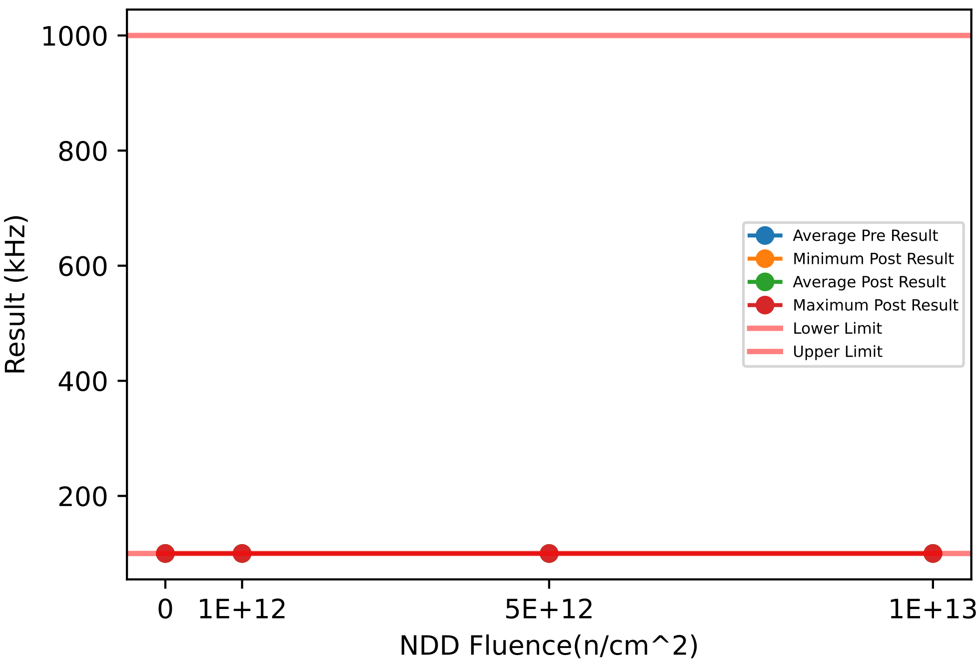
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

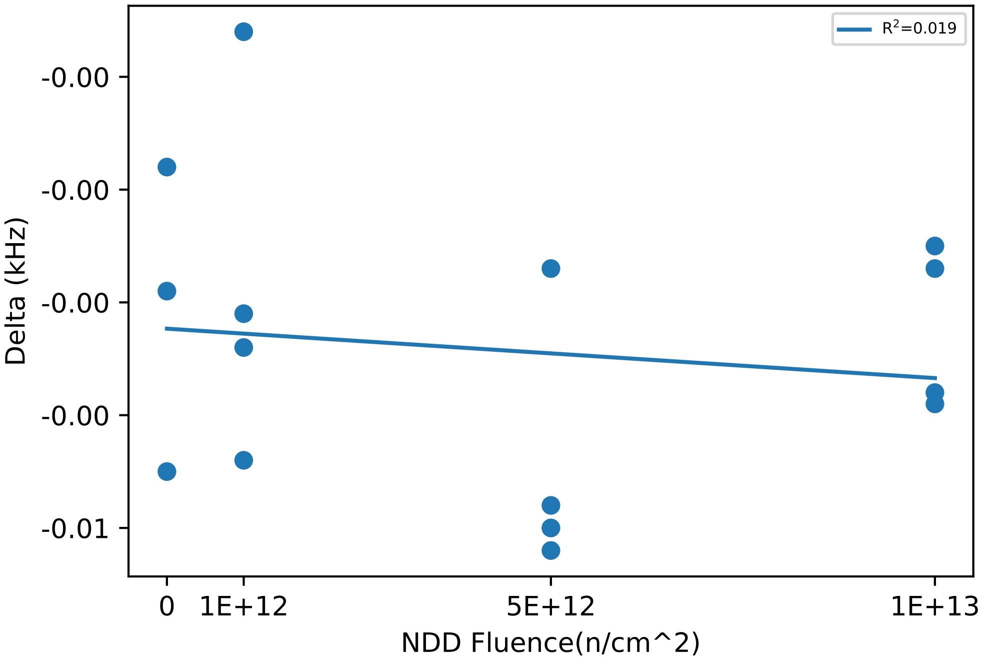
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.644	95.596	-0.0481
2	1e+12	NDD	93.235	93.196	-0.0385
3	1e+12	NDD	94.185	94.204	0.0188
4	1e+12	NDD	94.893	94.772	-0.1207
5	5e+12	NDD	90.615	90.679	0.064
6	5e+12	NDD	93.014	93.061	0.0467
7	5e+12	NDD	96.333	96.631	0.2983
8	5e+12	NDD	96.918	96.891	-0.0271
9	1e+13	NDD	95.639	95.878	0.2395
10	1e+13	NDD	96.082	96.092	0.0093
11	1e+13	NDD	97.484	97.366	-0.118
12	1e+13	NDD	95.522	95.49	-0.0317
13	0	CORRELATION	93.961	93.957	-0.0046
14	0	CORRELATION	96.094	96.105	0.0109
15	0	CORRELATION	92.847	92.838	-0.0089

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.847	94.301	96.094	1.6501	92.838	94.3	96.105	1.6605	-0.0089	-0.00086667	0.0109	0.010415
1e+12	93.235	94.489	95.644	1.0269	93.196	94.442	95.596	1.0083	-0.1207	-0.047125	0.0188	0.057256
5e+12	90.615	94.22	96.918	2.9549	90.679	94.315	96.891	2.9886	-0.0271	0.095475	0.2983	0.14087
1e+13	95.522	96.182	97.484	0.90114	95.49	96.207	97.366	0.81213	-0.118	0.024775	0.2395	0.15267

Device Test: 20.16 LEVEL|FREQ/SYNC/4.5/4.5/0/0/4.5/100kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

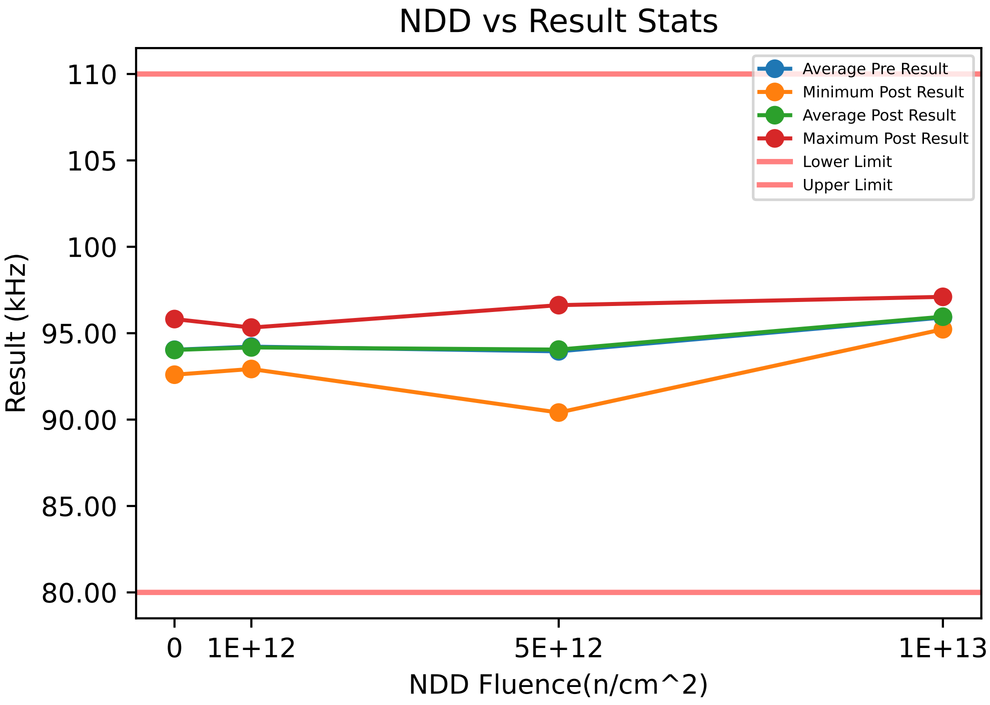
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

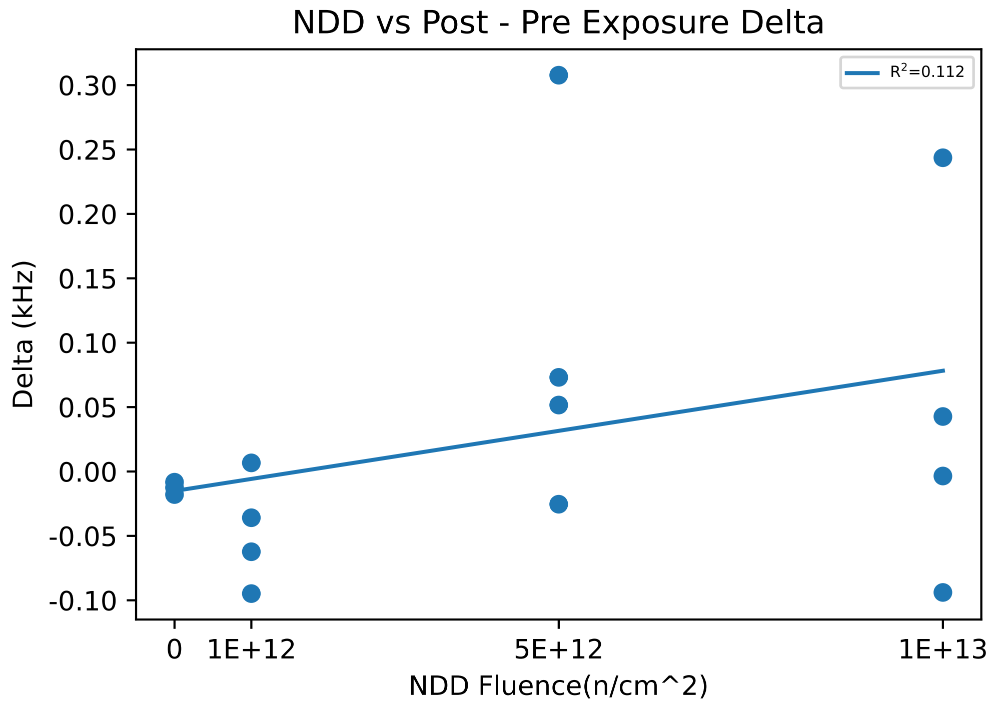
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.997	-0.0034
2	1e+12	NDD	100	99.999	-0.0044
3	1e+12	NDD	100	100	-0.0006
4	1e+12	NDD	100	99.998	-0.0031
5	5e+12	NDD	100	99.999	-0.0027
6	5e+12	NDD	100	99.999	-0.0048
7	5e+12	NDD	100	99.998	-0.0052
8	5e+12	NDD	100	99.999	-0.005
9	1e+13	NDD	100	99.999	-0.0039
10	1e+13	NDD	100	99.999	-0.0038
11	1e+13	NDD	100	100	-0.0025
12	1e+13	NDD	100	99.999	-0.0027
13	0	CORRELATION	100	99.999	-0.0018
14	0	CORRELATION	100	99.999	-0.0029
15	0	CORRELATION	100	99.999	-0.0045

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.0012342	99.999	99.999	99.999	0.00020817	-0.0045	-0.0030667	-0.0018	0.0013577
1e+12	100	100	100	0.0011888	99.997	99.999	100	0.0017689	-0.0044	-0.002875	-0.0006	0.0016153
5e+12	100	100	100	0.001063	99.998	99.999	99.999	0.00075443	-0.0052	-0.004425	-0.0027	0.0011615
1e+13	100	100	100	0.00069462	99.999	100	100	0.00075719	-0.0039	-0.003225	-0.0025	0.00072744

Device Test: 20.19 LEVEL|FREQ/RT/5/5/0/0/5/100kHz//@FSW_EXT_RT_A





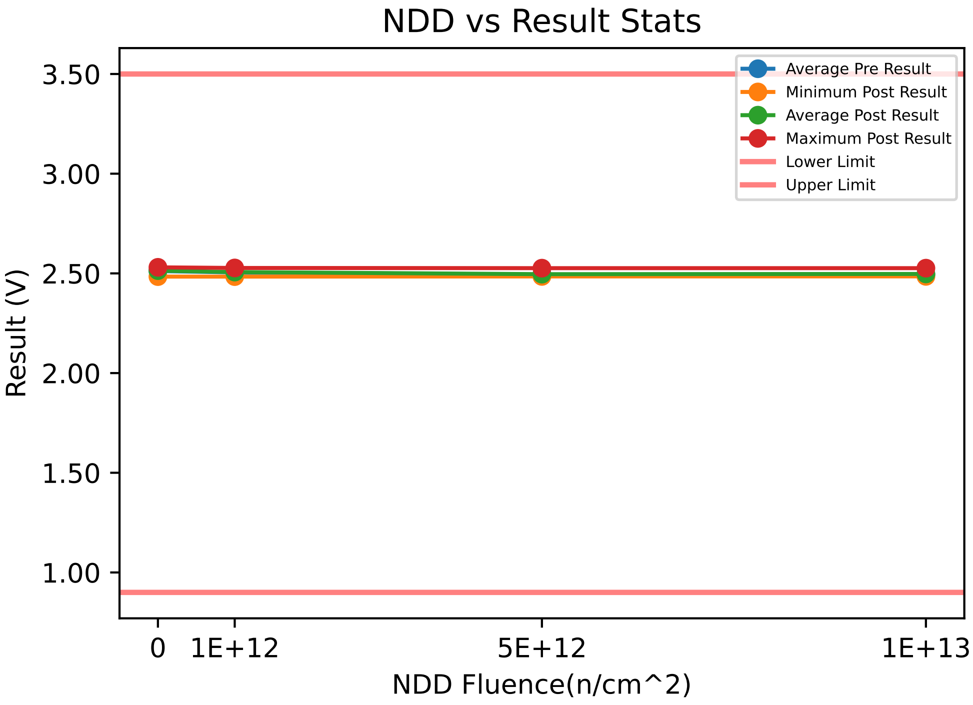
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

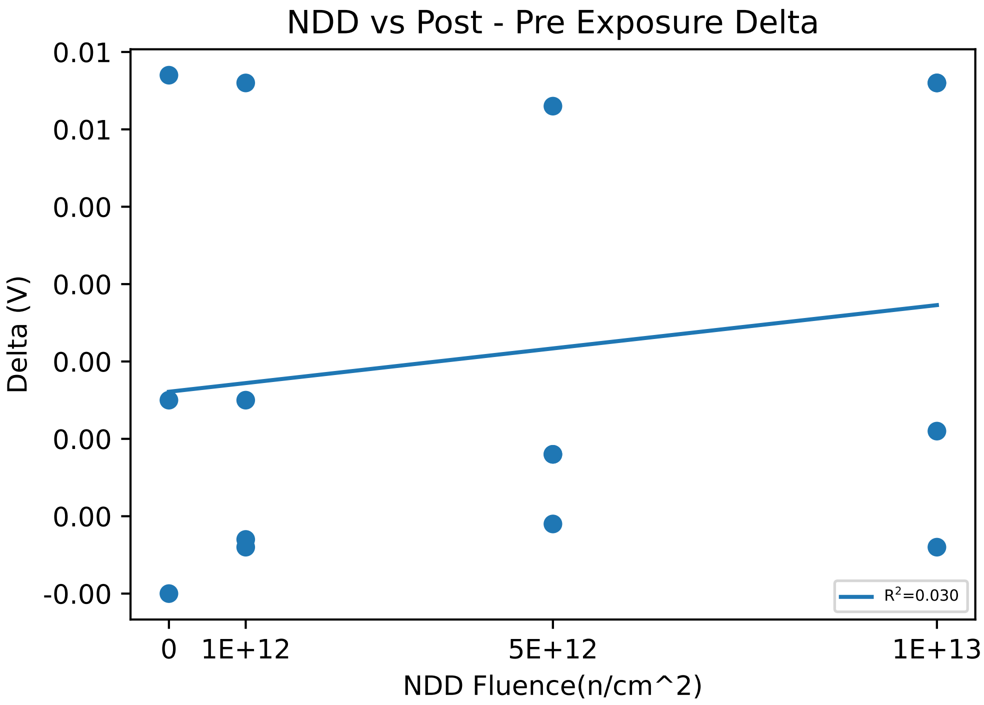
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.388	95.325	-0.0623
2	1e+12	NDD	92.965	92.929	-0.0359
3	1e+12	NDD	93.936	93.943	0.0067
4	1e+12	NDD	94.602	94.507	-0.0948
5	5e+12	NDD	90.335	90.408	0.0731
6	5e+12	NDD	92.735	92.786	0.0516
7	5e+12	NDD	96.083	96.391	0.3077
8	5e+12	NDD	96.648	96.623	-0.0254
9	1e+13	NDD	95.392	95.636	0.2436
10	1e+13	NDD	95.806	95.849	0.0427
11	1e+13	NDD	97.198	97.104	-0.0939
12	1e+13	NDD	95.232	95.228	-0.0035
13	0	CORRELATION	93.692	93.674	-0.0179
14	0	CORRELATION	95.831	95.819	-0.0125
15	0	CORRELATION	92.607	92.599	-0.0083

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.607	94.043	95.831	1.6406	92.599	94.03	95.819	1.6393	-0.0179	-0.0129	-0.0083	0.0048125
1e+12	92.965	94.223	95.388	1.0273	92.929	94.176	95.325	1.0068	-0.0948	-0.046575	0.0067	0.042915
5e+12	90.335	93.95	96.648	2.9652	90.408	94.052	96.623	2.9978	-0.0254	0.10175	0.3077	0.14366
1e+13	95.232	95.907	97.198	0.89392	95.228	95.954	97.104	0.80855	-0.0939	0.047225	0.2436	0.14268

Device Test: 20.2 LEVEL|HIGH_LEVEL/SYNC/4.5/4.5/0/0/4.5/500kHz//@SYNC_VIH_TH_LOW_4P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

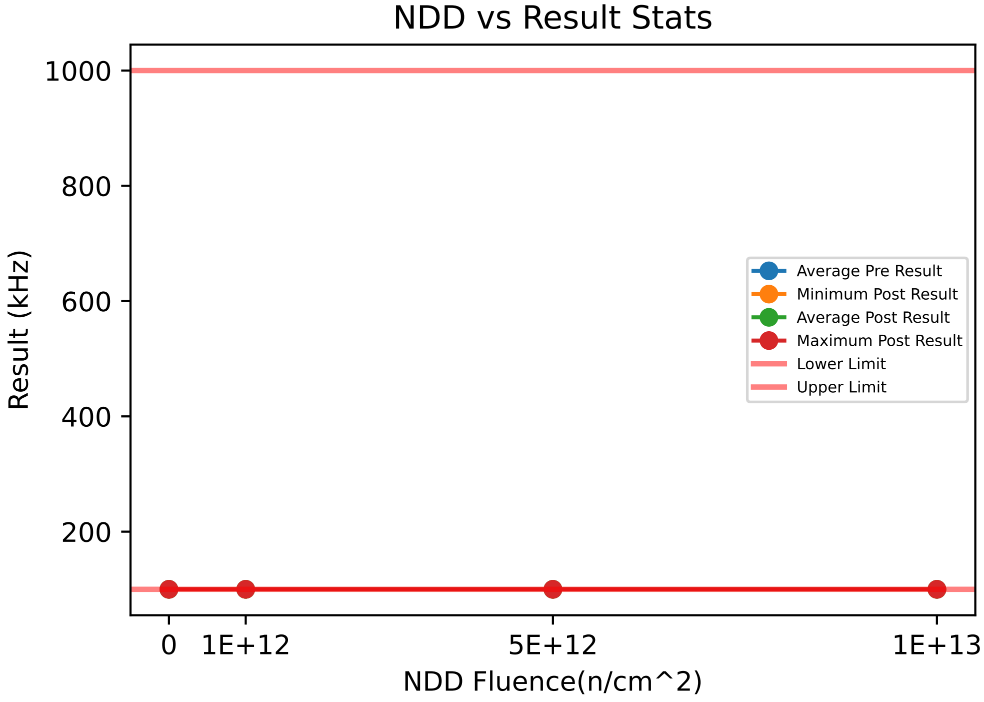
Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

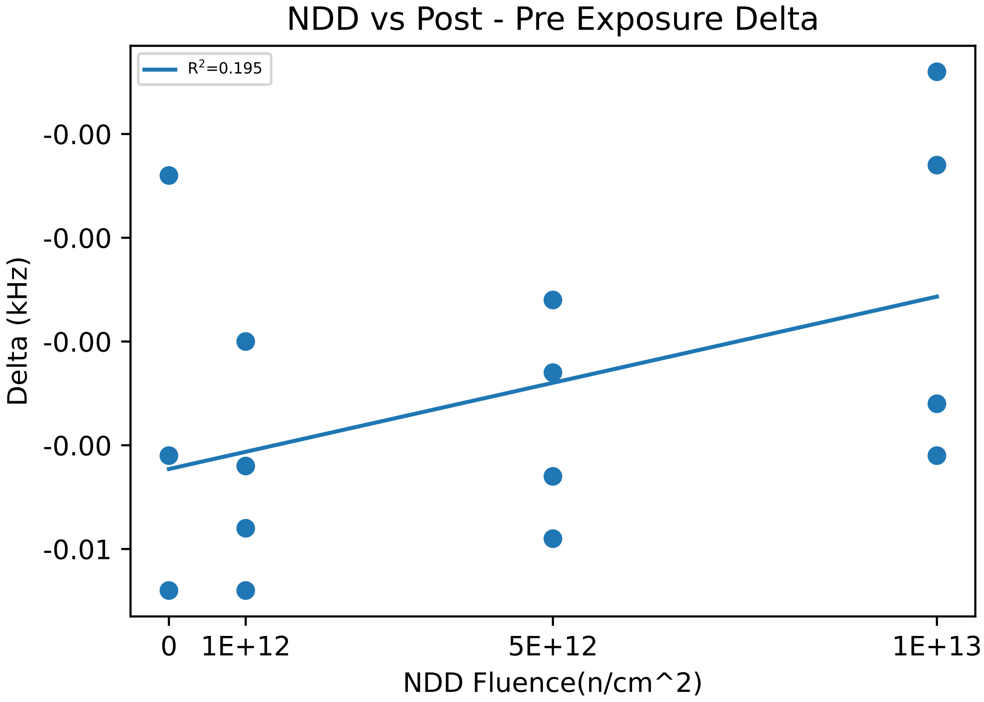
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.5266	2.5262	-0.0004
2	1e+12	NDD	2.5257	2.5272	0.0015
3	1e+12	NDD	2.4832	2.4888	0.0056
4	1e+12	NDD	2.4841	2.4838	-0.0003
5	5e+12	NDD	2.4839	2.4847	0.0008
6	5e+12	NDD	2.4832	2.4885	0.0053
7	5e+12	NDD	2.5263	2.5262	-0.0001
8	5e+12	NDD	2.4839	2.4847	0.0008
9	1e+13	NDD	2.4829	2.4885	0.0056
10	1e+13	NDD	2.5266	2.5262	-0.0004
11	1e+13	NDD	2.4839	2.485	0.0011
12	1e+13	NDD	2.4832	2.4888	0.0056
13	0	CORRELATION	2.4848	2.4838	-0.001
14	0	CORRELATION	2.5257	2.5272	0.0015
15	0	CORRELATION	2.5247	2.5304	0.0057

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4848	2.5117	2.5257	0.02333	2.4838	2.5138	2.5304	0.02603	-0.001	0.0020667	0.0057	0.0033858
1e+12	2.4832	2.5049	2.5266	0.024543	2.4838	2.5065	2.5272	0.023418	-0.0004	0.0016	0.0056	0.0028059
5e+12	2.4832	2.4943	2.5263	0.021319	2.4847	2.496	2.5262	0.020196	-0.0001	0.0017	0.0053	0.0024372
1e+13	2.4829	2.4942	2.5266	0.021637	2.485	2.4971	2.5262	0.01946	-0.0004	0.002975	0.0056	0.0030923

Device Test: 20.20 LEVEL|FREQ/SYNC/5/5/0/0/5/100kHz//@FREQ_SYNC_EXT





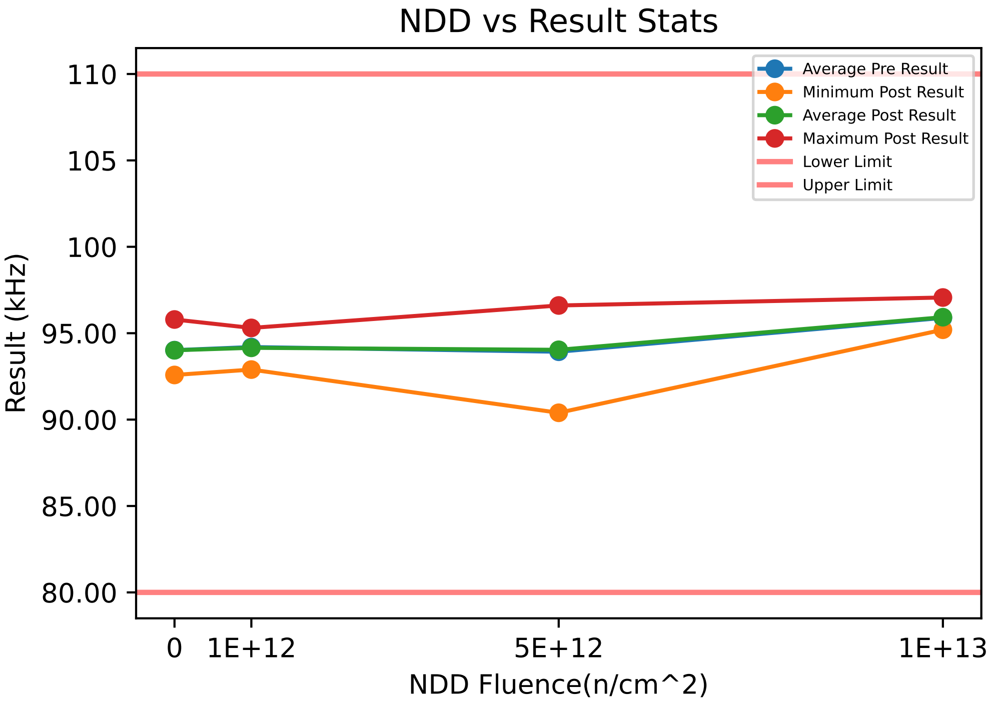
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

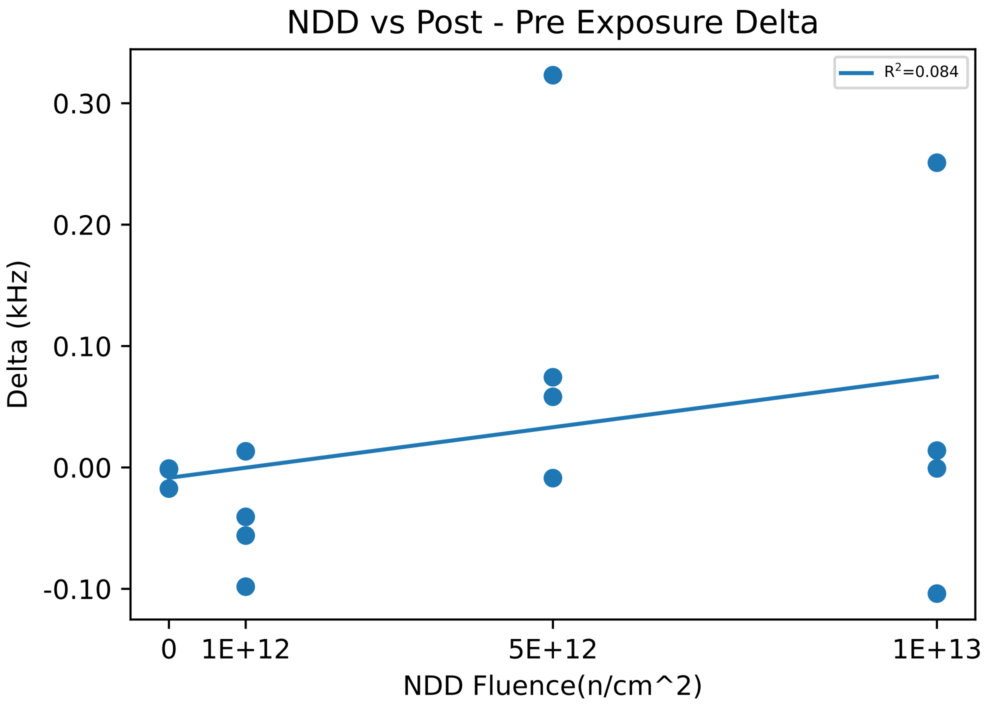
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.998	-0.0048
2	1e+12	NDD	100	99.999	-0.0042
3	1e+12	NDD	100	99.999	-0.003
4	1e+12	NDD	100	99.997	-0.0054
5	5e+12	NDD	100	99.999	-0.0026
6	5e+12	NDD	100	99.999	-0.0043
7	5e+12	NDD	100	99.998	-0.0033
8	5e+12	NDD	100	99.998	-0.0049
9	1e+13	NDD	100	99.999	-0.0041
10	1e+13	NDD	100	99.998	-0.0036
11	1e+13	NDD	100	100	-0.0004
12	1e+13	NDD	100	100	-0.0013
13	0	CORRELATION	100	99.998	-0.0041
14	0	CORRELATION	100	99.999	-0.0054
15	0	CORRELATION	100	100	-0.0014

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.0014224	99.998	99.999	100	0.0015044	-0.0054	-0.0036333	-0.0014	0.0020404
1e+12	100	100	100	0.00046904	99.997	99.998	99.999	0.0011269	-0.0054	-0.00435	-0.003	0.0010247
5e+12	100	100	100	0.0012662	99.998	99.998	99.999	0.00078049	-0.0049	-0.003775	-0.0026	0.0010243
1e+13	100	100	100	0.00096782	99.998	99.999	100	0.0014629	-0.0041	-0.00235	-0.0004	0.0017823

Device Test: 20.23 LEVEL|FREQ/RT/12/12/0/0/5/100kHz//@FSW_EXT_RT_A


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

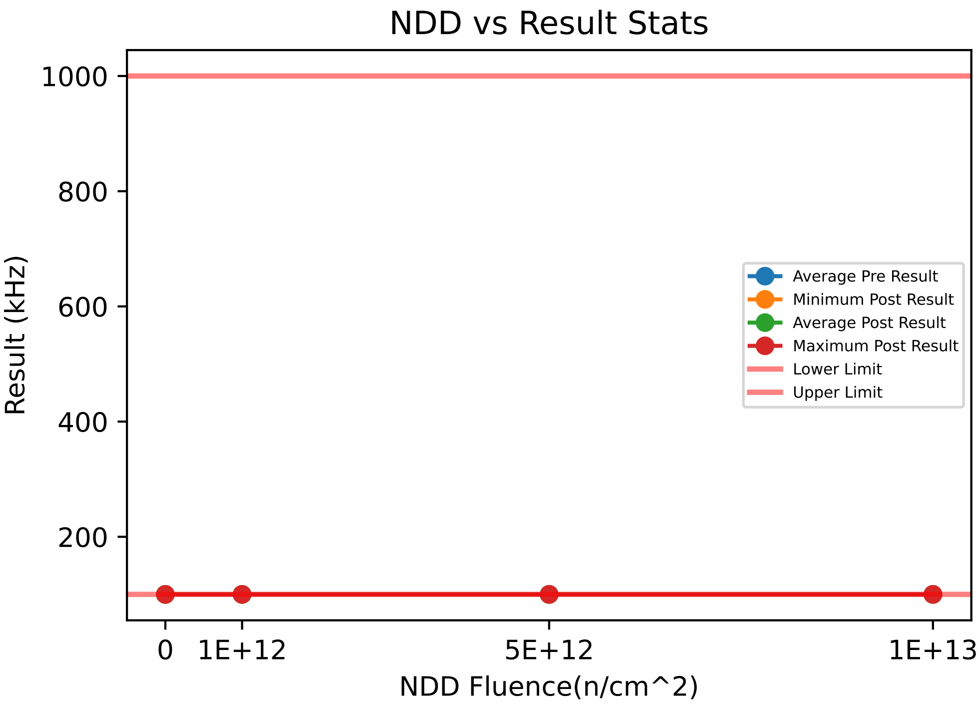
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

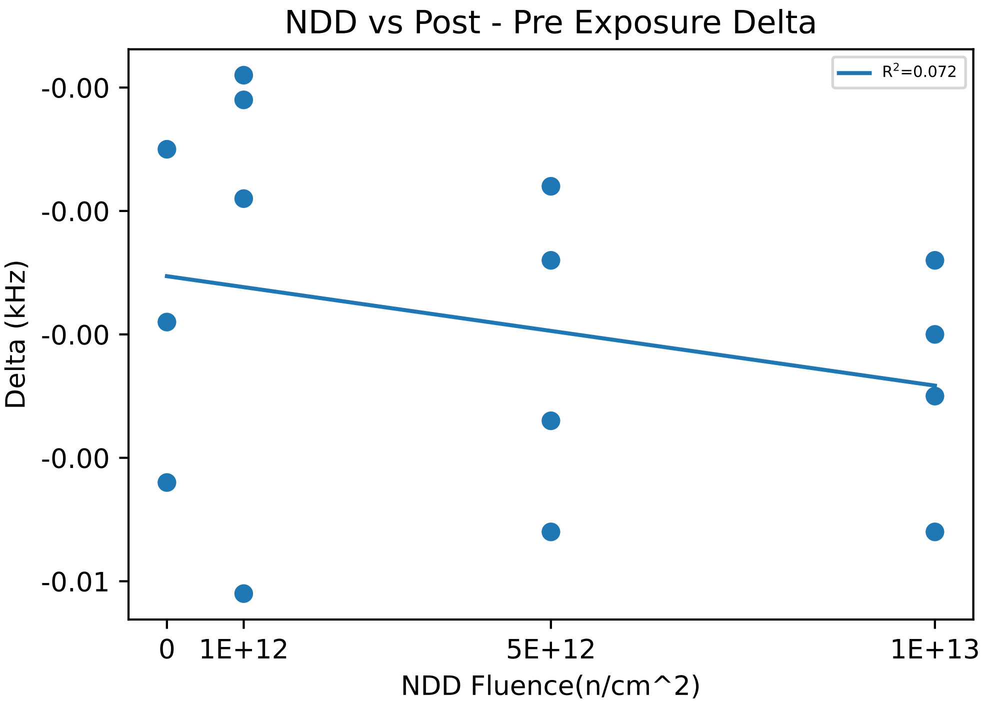
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.362	95.306	-0.0561
2	1e+12	NDD	92.935	92.895	-0.0407
3	1e+12	NDD	93.918	93.931	0.0133
4	1e+12	NDD	94.582	94.484	-0.0982
5	5e+12	NDD	90.32	90.395	0.0743
6	5e+12	NDD	92.719	92.777	0.0582
7	5e+12	NDD	96.057	96.38	0.3231
8	5e+12	NDD	96.613	96.605	-0.0088
9	1e+13	NDD	95.379	95.63	0.251
10	1e+13	NDD	95.79	95.804	0.0139
11	1e+13	NDD	97.169	97.065	-0.1039
12	1e+13	NDD	95.202	95.201	-0.0008
13	0	CORRELATION	93.66	93.659	-0.0009
14	0	CORRELATION	95.795	95.793	-0.0017
15	0	CORRELATION	92.6	92.583	-0.0174

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.6	94.018	95.795	1.6271	92.583	94.012	95.793	1.6339	-0.0174	-0.0066667	-0.0009	0.0093039
1e+12	92.935	94.199	95.362	1.0288	92.895	94.154	95.306	1.0118	-0.0982	-0.045425	0.0133	0.04608
5e+12	90.32	93.927	96.613	2.9563	90.395	94.039	96.605	2.9964	-0.0088	0.1117	0.3231	0.14545
1e+13	95.202	95.885	97.169	0.89089	95.201	95.925	97.065	0.80127	-0.1039	0.04005	0.251	0.15008

Device Test: 20.24 LEVEL|FREQ/SYNC/12/12/0/0/5/100kHz//@FREQ_SYNC_EXT





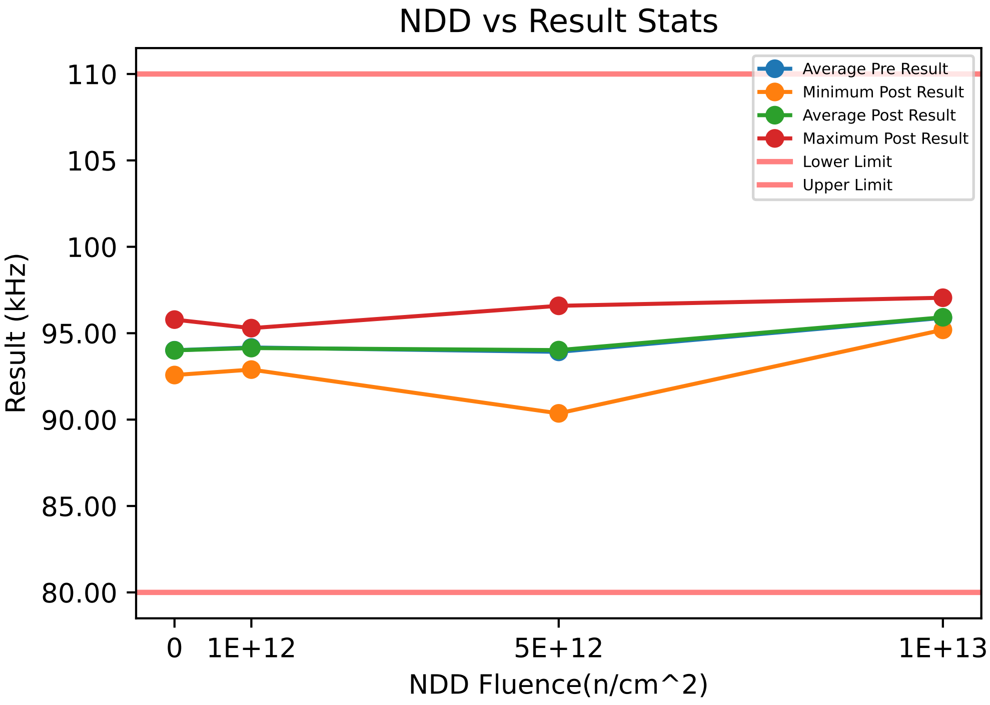
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

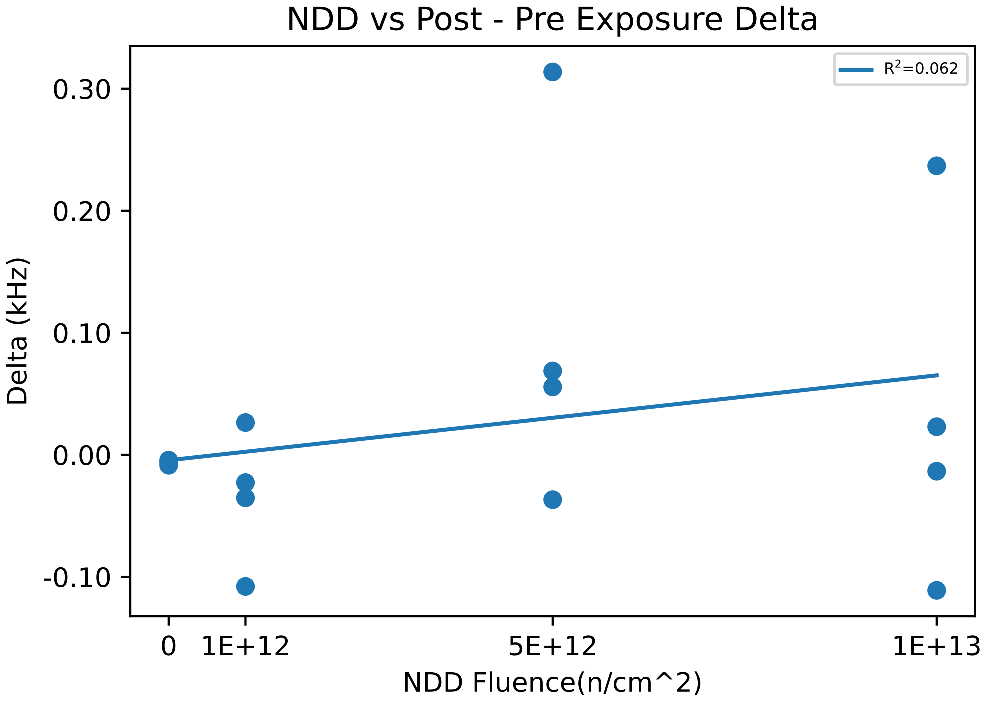
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.999	-0.0019
2	1e+12	NDD	100	100	-0.0009
3	1e+12	NDD	100	100	-0.0011
4	1e+12	NDD	100	99.997	-0.0051
5	5e+12	NDD	100	99.999	-0.0037
6	5e+12	NDD	100	99.999	-0.0024
7	5e+12	NDD	100	99.999	-0.0018
8	5e+12	NDD	100	99.999	-0.0046
9	1e+13	NDD	100	99.999	-0.0046
10	1e+13	NDD	100	99.997	-0.0035
11	1e+13	NDD	100	99.999	-0.0024
12	1e+13	NDD	100	100	-0.003
13	0	CORRELATION	100	99.998	-0.0042
14	0	CORRELATION	100	100	-0.0029
15	0	CORRELATION	100	100	-0.0015

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.00073711	99.998	99.999	100	0.0016523	-0.0042	-0.0028667	-0.0015	0.0013503
1e+12	100	100	100	0.00058523	99.997	99.999	100	0.0016721	-0.0051	-0.00225	-0.0009	0.0019485
5e+12	100	100	100	0.0012247	99.999	99.999	99.999	5e-05	-0.0046	-0.003125	-0.0018	0.0012633
1e+13	100	100	100	0.00145	99.997	99.999	100	0.0012028	-0.0046	-0.003375	-0.0024	0.00093229

Device Test: 20.27 LEVEL|FREQ/RT/14/14/0/0/5/100kHz//@FSW_EXT_RT_A





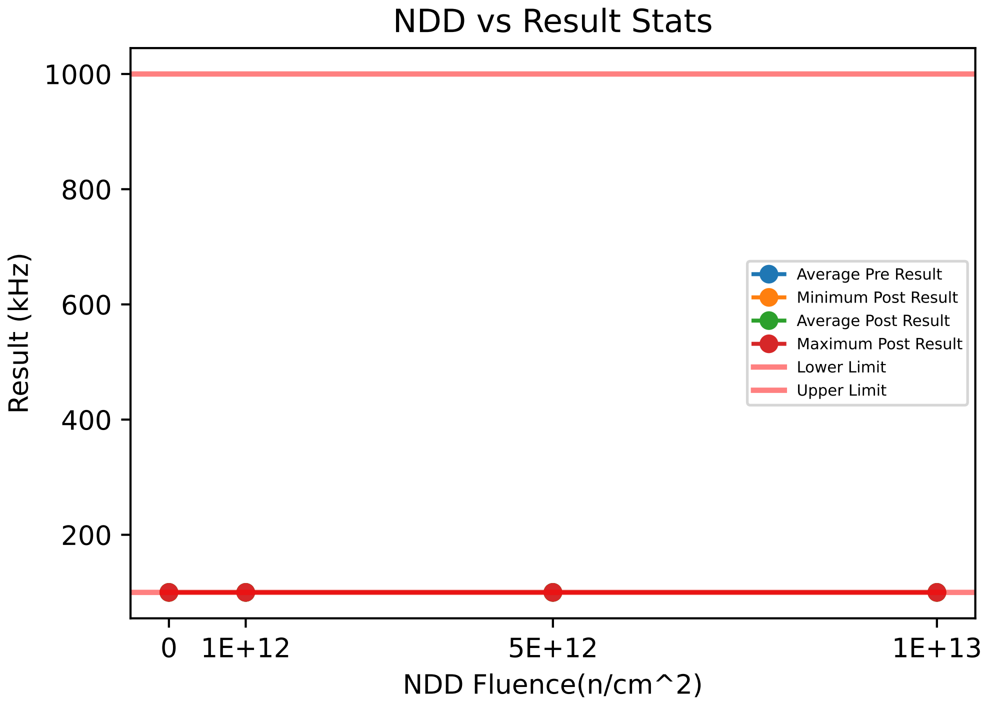
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

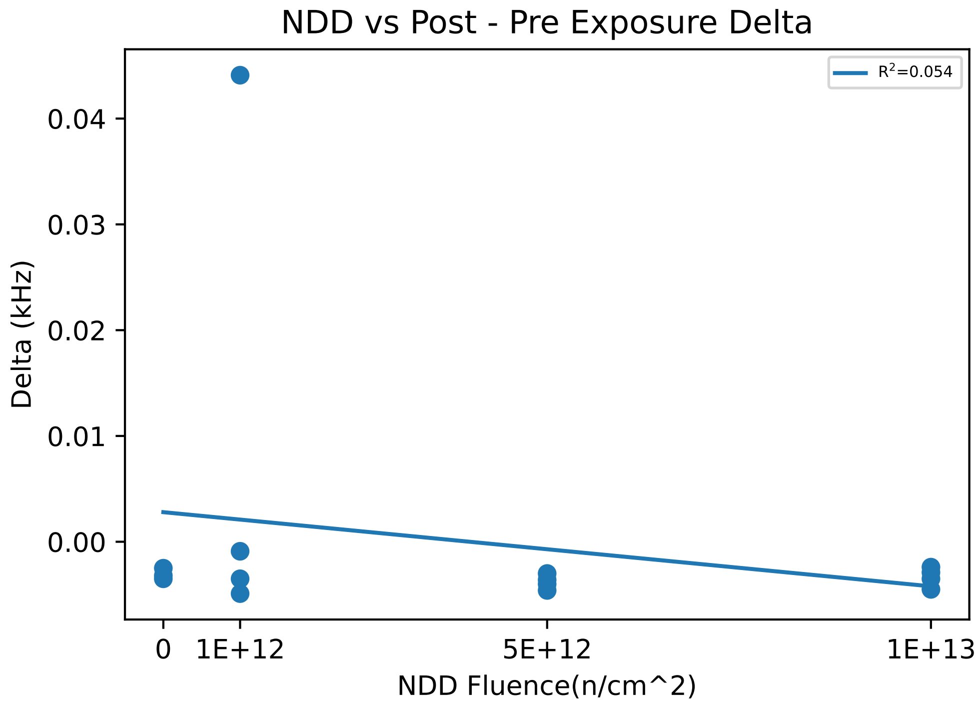
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.329	95.293	-0.0353
2	1e+12	NDD	92.916	92.894	-0.0228
3	1e+12	NDD	93.893	93.92	0.0264
4	1e+12	NDD	94.561	94.453	-0.1079
5	5e+12	NDD	90.305	90.361	0.0556
6	5e+12	NDD	92.709	92.778	0.0687
7	5e+12	NDD	96.048	96.361	0.3137
8	5e+12	NDD	96.621	96.585	-0.0368
9	1e+13	NDD	95.384	95.621	0.2368
10	1e+13	NDD	95.79	95.813	0.023
11	1e+13	NDD	97.163	97.052	-0.1111
12	1e+13	NDD	95.209	95.196	-0.0135
13	0	CORRELATION	93.659	93.655	-0.0044
14	0	CORRELATION	95.793	95.787	-0.0059
15	0	CORRELATION	92.588	92.579	-0.0086

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.588	94.013	95.793	1.6316	92.579	94.007	95.787	1.6326	-0.0086	-0.0063	-0.0044	0.0021284
1e+12	92.916	94.175	95.329	1.0236	92.894	94.14	95.293	1.005	-0.1079	-0.0349	0.0264	0.055478
5e+12	90.305	93.921	96.621	2.9642	90.361	94.021	96.585	2.9996	-0.0368	0.1003	0.3137	0.14981
1e+13	95.209	95.887	97.163	0.88514	95.196	95.92	97.052	0.79731	-0.1111	0.0338	0.2368	0.1467

Device Test: 20.28 LEVEL|FREQ/SYNC/14/14/0/0/5/100kHz//@FREQ_SYNC_EXT





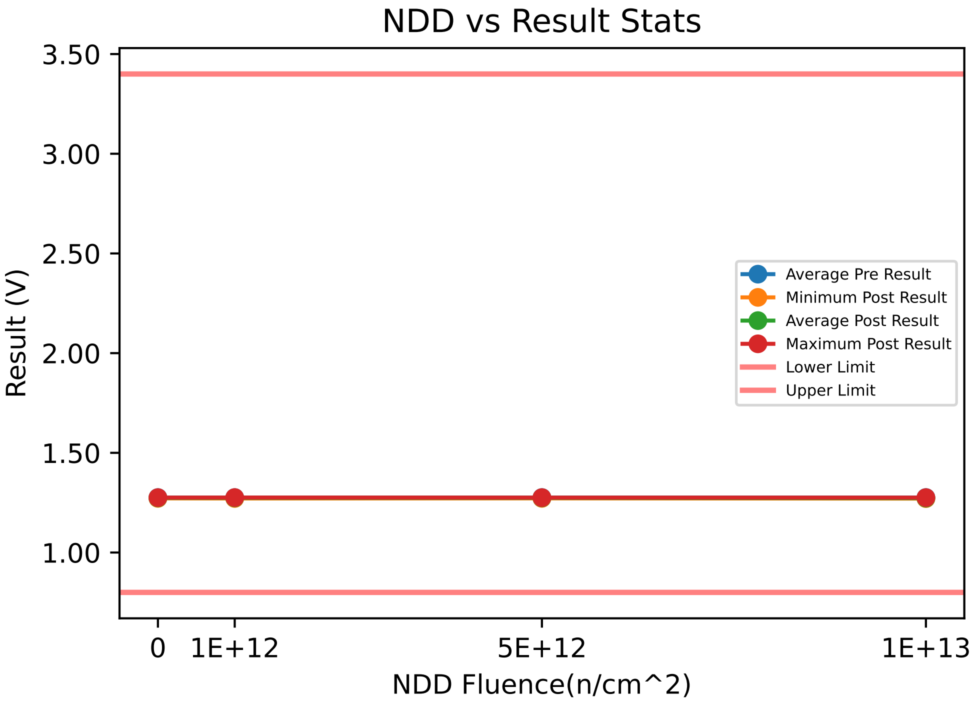
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

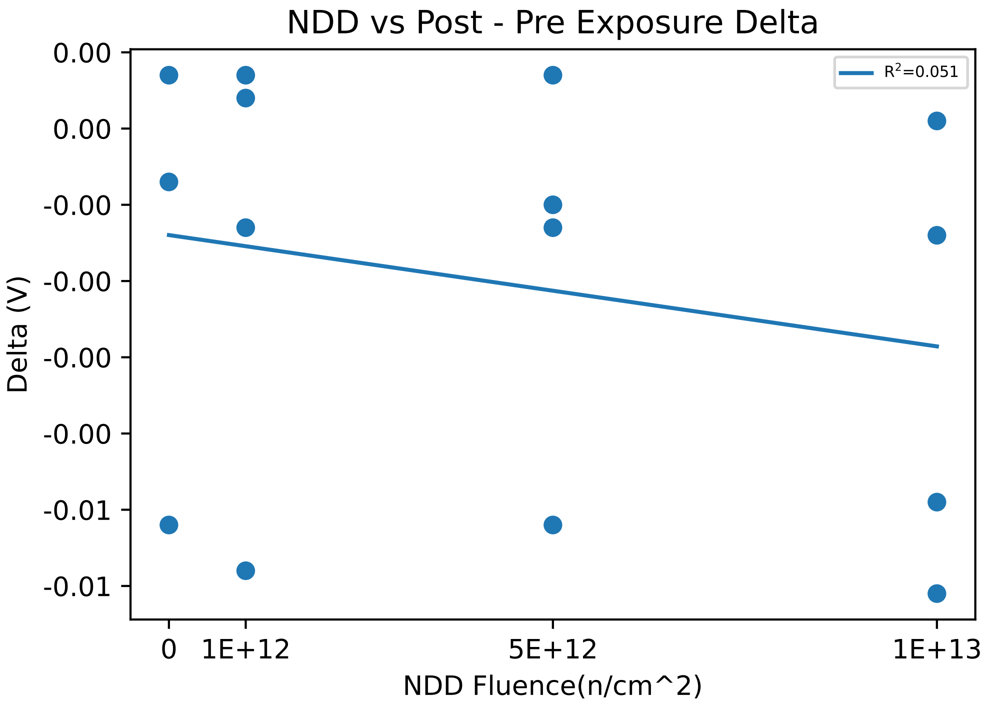
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.998	-0.0035
2	1e+12	NDD	100	100	-0.0009
3	1e+12	NDD	99.956	100	0.0441
4	1e+12	NDD	100	99.997	-0.0049
5	5e+12	NDD	100	99.999	-0.0046
6	5e+12	NDD	100	100	-0.003
7	5e+12	NDD	100	99.999	-0.004
8	5e+12	NDD	100	99.999	-0.0036
9	1e+13	NDD	100	100	-0.0029
10	1e+13	NDD	100	99.998	-0.0045
11	1e+13	NDD	100	99.999	-0.0024
12	1e+13	NDD	100	99.999	-0.0035
13	0	CORRELATION	100	99.999	-0.0025
14	0	CORRELATION	100	99.999	-0.0035
15	0	CORRELATION	100	100	-0.0032

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.0012	99.999	99.999	100	0.00092916	-0.0035	-0.0030667	-0.0025	0.00051316
1e+12	99.956	99.99	100	0.022723	99.997	99.999	100	0.0015349	-0.0049	0.0087	0.0441	0.023658
5e+12	100	100	100	0.00029439	99.999	99.999	100	0.00068799	-0.0046	-0.0038	-0.003	0.0006733
1e+13	100	100	100	0.00087369	99.998	99.999	100	0.001072	-0.0045	-0.003325	-0.0024	0.00090323

Device Test: 20.3 LEVEL|LOW_LEVEL/SYNC/4.8/4.8/0/0/4.5/500kHz//@SYNC_VIL_TH_HIGH_4P5





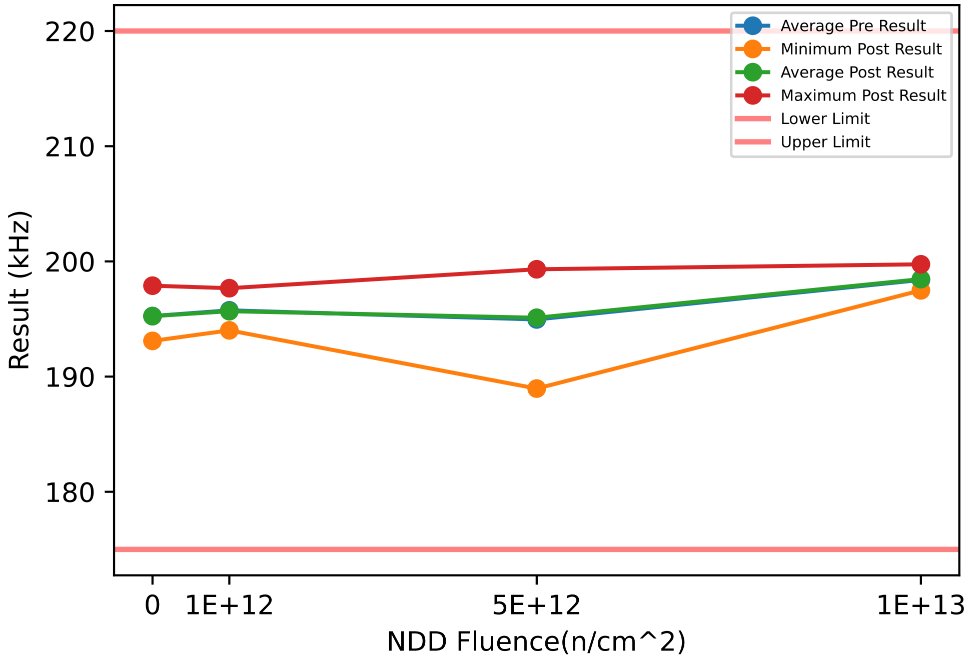
Test Results (Lower Limit = 0.8, Upper Limit = 3.4 (V))

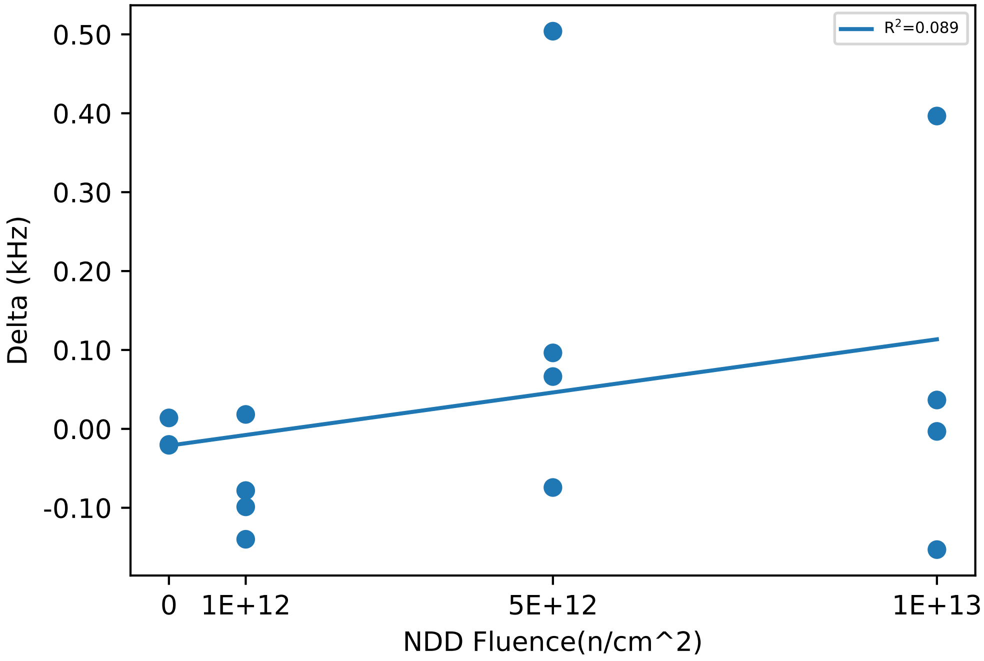
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2753	1.2757	0.0004
2	1e+12	NDD	1.2757	1.2744	-0.0013
3	1e+12	NDD	1.2768	1.271	-0.0058
4	1e+12	NDD	1.2747	1.2754	0.0007
5	5e+12	NDD	1.276	1.2747	-0.0013
6	5e+12	NDD	1.2768	1.2716	-0.0052
7	5e+12	NDD	1.2747	1.2754	0.0007
8	5e+12	NDD	1.2757	1.2747	-0.001
9	1e+13	NDD	1.2765	1.2716	-0.0049
10	1e+13	NDD	1.2753	1.2754	0.0001
11	1e+13	NDD	1.2754	1.274	-0.0014
12	1e+13	NDD	1.2765	1.2704	-0.0061
13	0	CORRELATION	1.2747	1.2754	0.0007
14	0	CORRELATION	1.2757	1.275	-0.0007
15	0	CORRELATION	1.2768	1.2716	-0.0052

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2747	1.2757	1.2768	0.0010504	1.2716	1.274	1.2754	0.0020881	-0.0052	-0.0017333	0.0007	0.0030827
1e+12	1.2747	1.2756	1.2768	0.00088459	1.271	1.2741	1.2757	0.0021562	-0.0058	-0.0015	0.0007	0.0029989
5e+12	1.2747	1.2758	1.2768	0.00086795	1.2716	1.2741	1.2754	0.001699	-0.0052	-0.0017	0.0007	0.002494
1e+13	1.2753	1.2759	1.2765	0.00066521	1.2704	1.2729	1.2754	0.002265	-0.0061	-0.003075	0.0001	0.0029079

Device Test: 20.31 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/200kHz//@FSW_EXT_RT_B


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

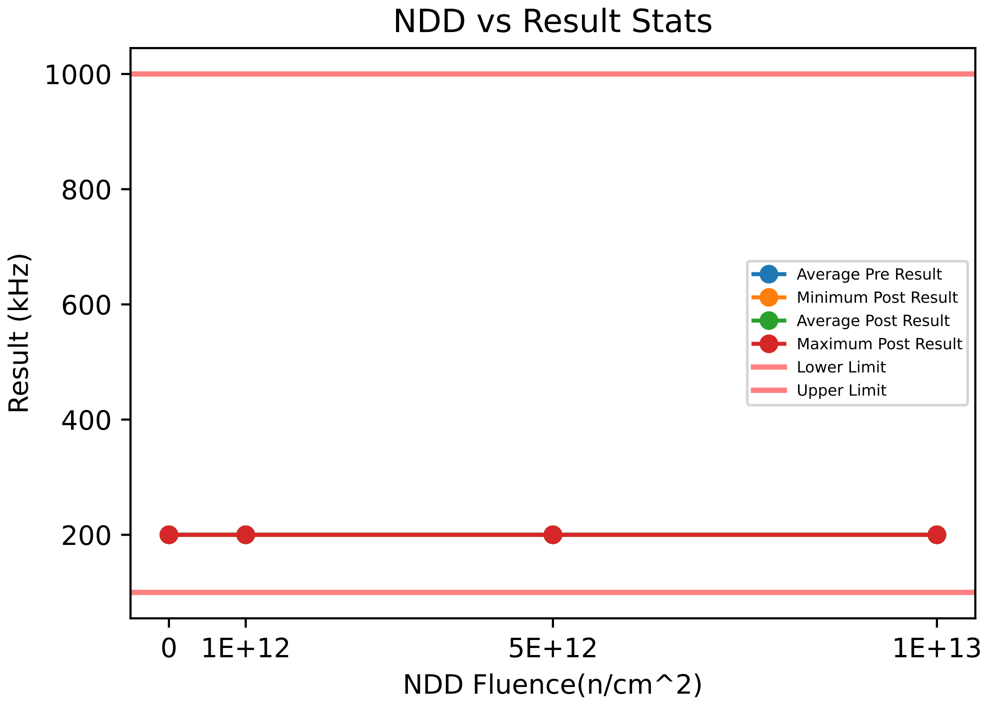
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

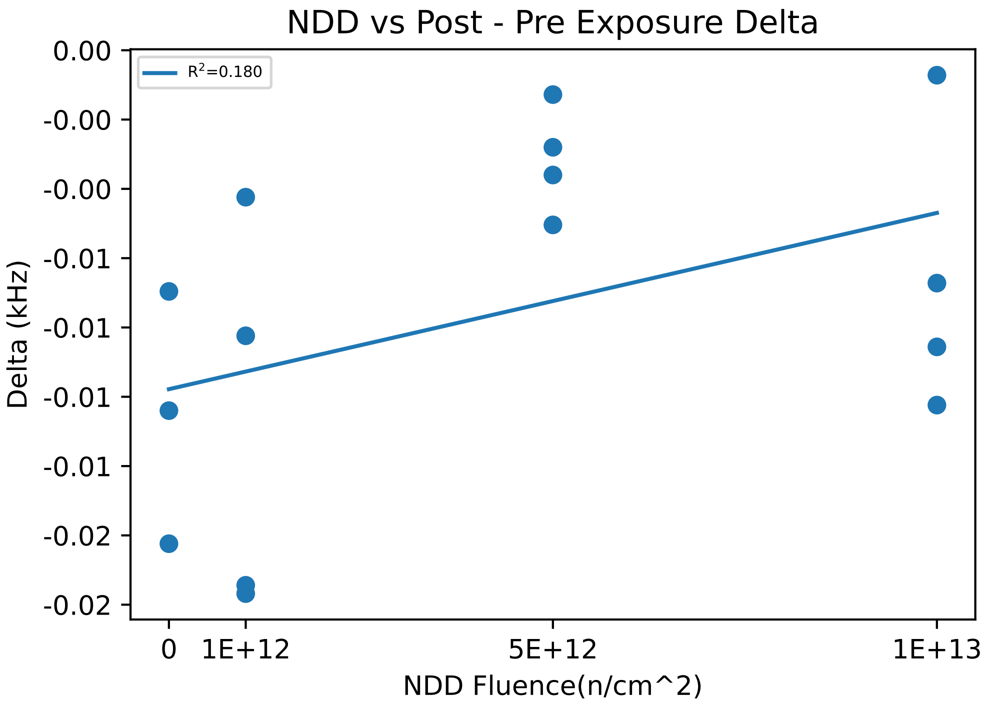
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.77	197.67	-0.0988
2	1e+12	NDD	194.09	194.01	-0.0782
3	1e+12	NDD	195.05	195.07	0.0183
4	1e+12	NDD	196.09	195.95	-0.1399
5	5e+12	NDD	188.87	188.96	0.0963
6	5e+12	NDD	193.45	193.51	0.0663
7	5e+12	NDD	198.14	198.65	0.504
8	5e+12	NDD	199.39	199.32	-0.0743
9	1e+13	NDD	198	198.39	0.3965
10	1e+13	NDD	198.19	198.22	0.0366
11	1e+13	NDD	199.9	199.75	-0.153
12	1e+13	NDD	197.49	197.49	-0.0032
13	0	CORRELATION	194.77	194.75	-0.0208
14	0	CORRELATION	197.91	197.89	-0.0197
15	0	CORRELATION	193.08	193.1	0.0139

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.08	195.26	197.91	2.4494	193.1	195.25	197.89	2.4346	-0.0208	-0.0088667	0.0139	0.019724
1e+12	194.09	195.75	197.77	1.5751	194.01	195.68	197.67	1.5488	-0.1399	-0.07465	0.0183	0.067065
5e+12	188.87	194.96	199.39	4.8025	188.96	195.11	199.32	4.8495	-0.0743	0.14807	0.504	0.24866
1e+13	197.49	198.39	199.9	1.0475	197.49	198.46	199.75	0.94328	-0.153	0.069225	0.3965	0.23295

Device Test: 20.32 LEVEL|FREQ/SYNC/4.5/4.5/0/0/4.5/200kHz//@FREQ_SYNC_EXT





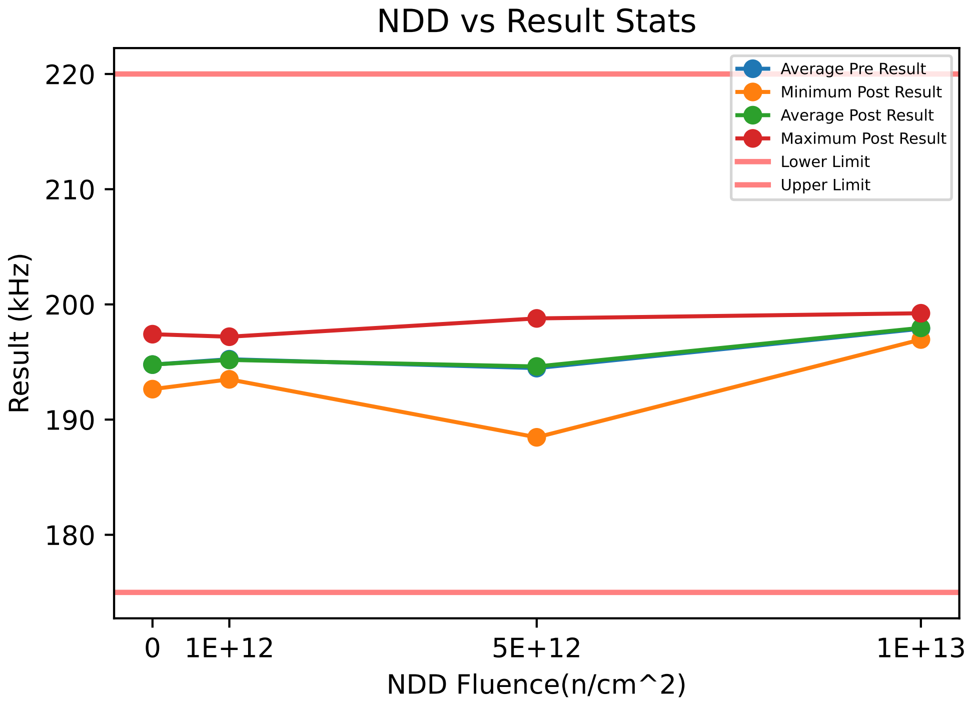
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

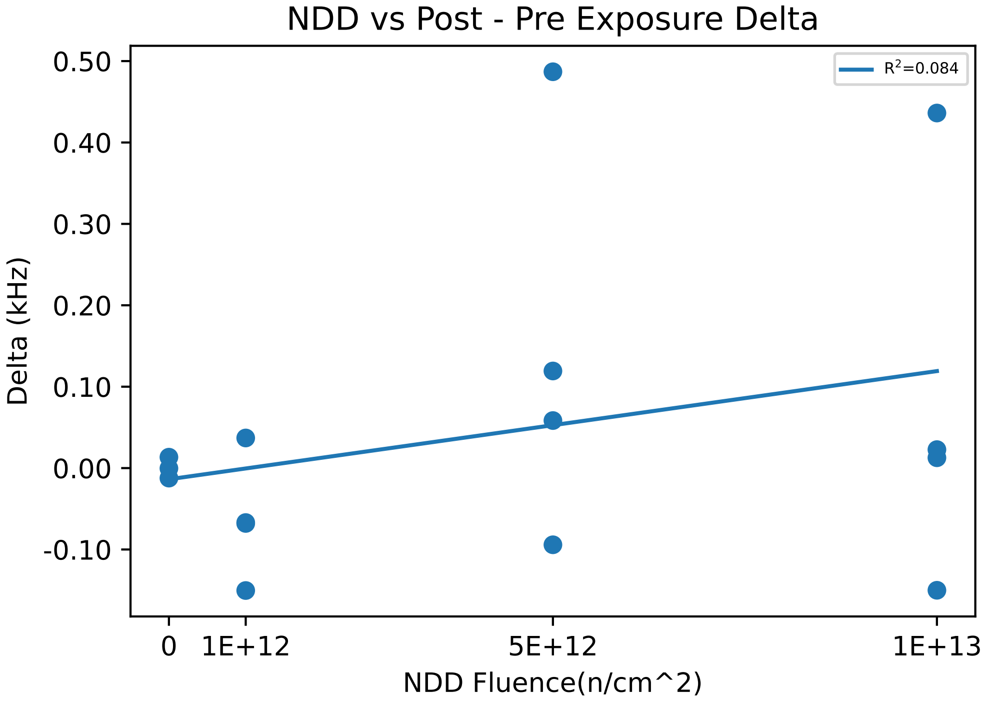
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200.01	199.99	-0.0193
2	1e+12	NDD	200.01	199.99	-0.0196
3	1e+12	NDD	200.01	200	-0.0053
4	1e+12	NDD	200.01	200	-0.0103
5	5e+12	NDD	200	200	-0.0045
6	5e+12	NDD	200.01	200	-0.0035
7	5e+12	NDD	200	200	-0.0063
8	5e+12	NDD	200	200	-0.0016
9	1e+13	NDD	200	200	-0.0009
10	1e+13	NDD	200.01	200	-0.0128
11	1e+13	NDD	200	200	-0.0084
12	1e+13	NDD	200.01	200	-0.0107
13	0	CORRELATION	200.01	200	-0.013
14	0	CORRELATION	200	200	-0.0087
15	0	CORRELATION	200.01	200	-0.0178

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200.01	200.01	0.0047032	200	200	200	0.00015275	-0.0178	-0.013167	-0.0087	0.0045523
1e+12	200.01	200.01	200.01	0.0031838	199.99	200	200	0.0060506	-0.0196	-0.013625	-0.0053	0.0070301
5e+12	200	200	200.01	0.0029331	200	200	200	0.0038956	-0.0063	-0.003975	-0.0016	0.0019619
1e+13	200	200.01	200.01	0.0025936	200	200	200	0.0032762	-0.0128	-0.0082	-0.0009	0.0051878

Device Test: 20.33 LEVEL|FREQ/RT/5/5/0/0/5/200kHz//@FSW_EXT_RT_B





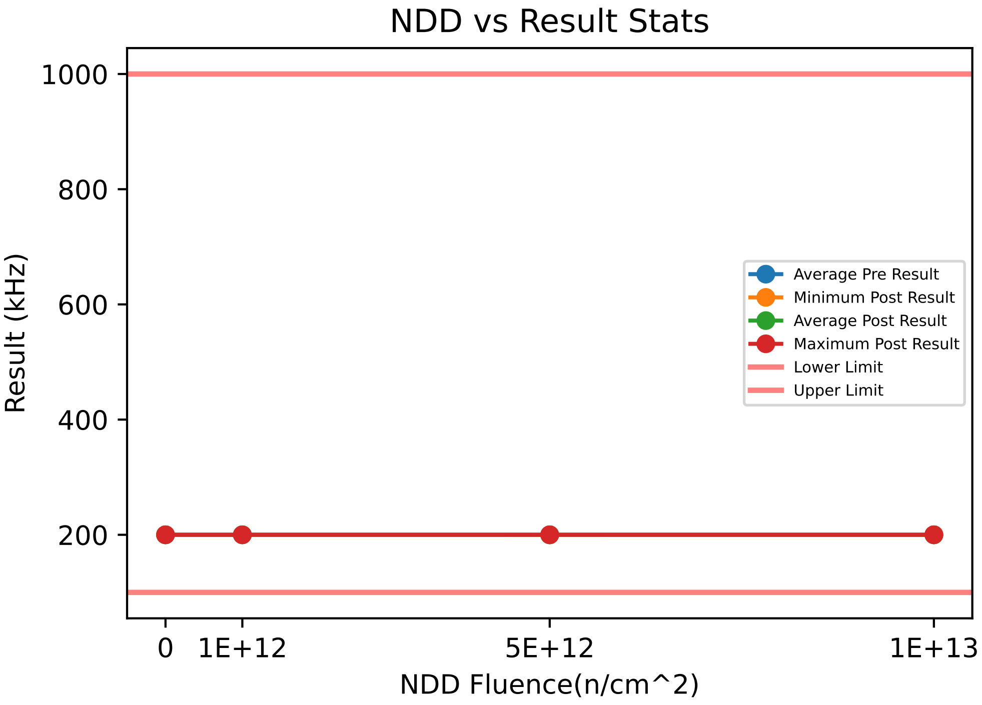
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

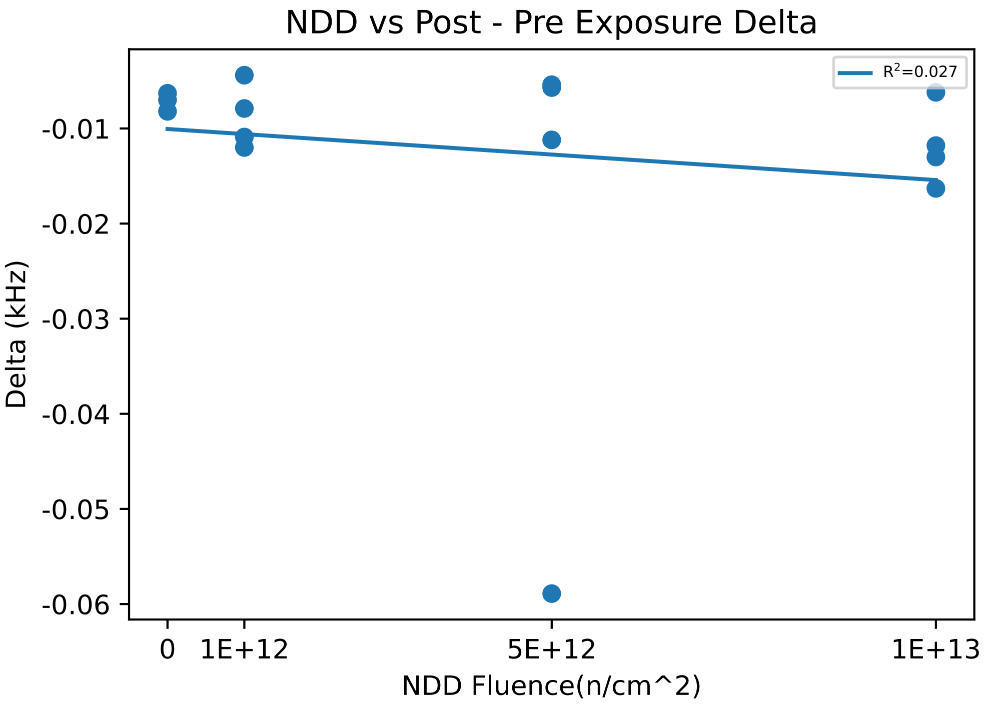
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.26	197.19	-0.0669
2	1e+12	NDD	193.56	193.49	-0.068
3	1e+12	NDD	194.57	194.61	0.037
4	1e+12	NDD	195.57	195.42	-0.1504
5	5e+12	NDD	188.34	188.46	0.1193
6	5e+12	NDD	192.94	193	0.0584
7	5e+12	NDD	197.71	198.2	0.4869
8	5e+12	NDD	198.88	198.78	-0.0942
9	1e+13	NDD	197.5	197.93	0.4362
10	1e+13	NDD	197.72	197.74	0.0127
11	1e+13	NDD	199.38	199.23	-0.1501
12	1e+13	NDD	196.93	196.95	0.0227
13	0	CORRELATION	194.27	194.27	-0.0003
14	0	CORRELATION	197.4	197.41	0.0134
15	0	CORRELATION	192.66	192.64	-0.0123

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.66	194.77	197.4	2.4127	192.64	194.77	197.41	2.4254	-0.0123	0.00026667	0.0134	0.012859
1e+12	193.56	195.24	197.26	1.5772	193.49	195.18	197.19	1.5588	-0.1504	-0.062075	0.037	0.076758
5e+12	188.34	194.47	198.88	4.8242	188.46	194.61	198.78	4.8541	-0.0942	0.1426	0.4869	0.24647
1e+13	196.93	197.88	199.38	1.0533	196.95	197.96	199.23	0.94559	-0.1501	0.080375	0.4362	0.25009

Device Test: 20.34 LEVEL|FREQ/SYNC/5/5/0/0/5/200kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

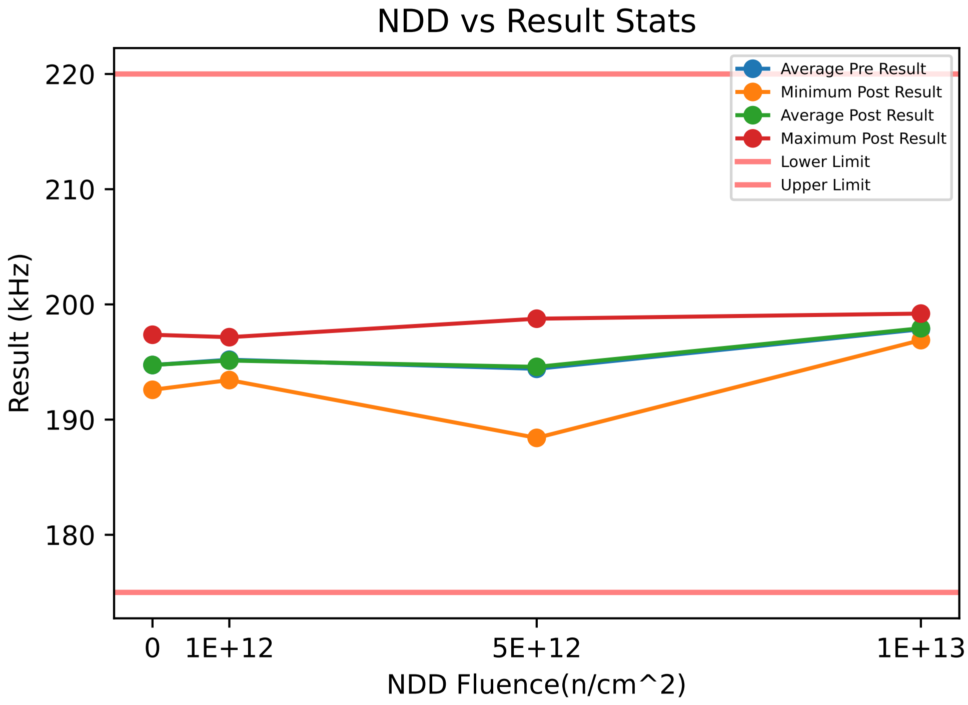
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

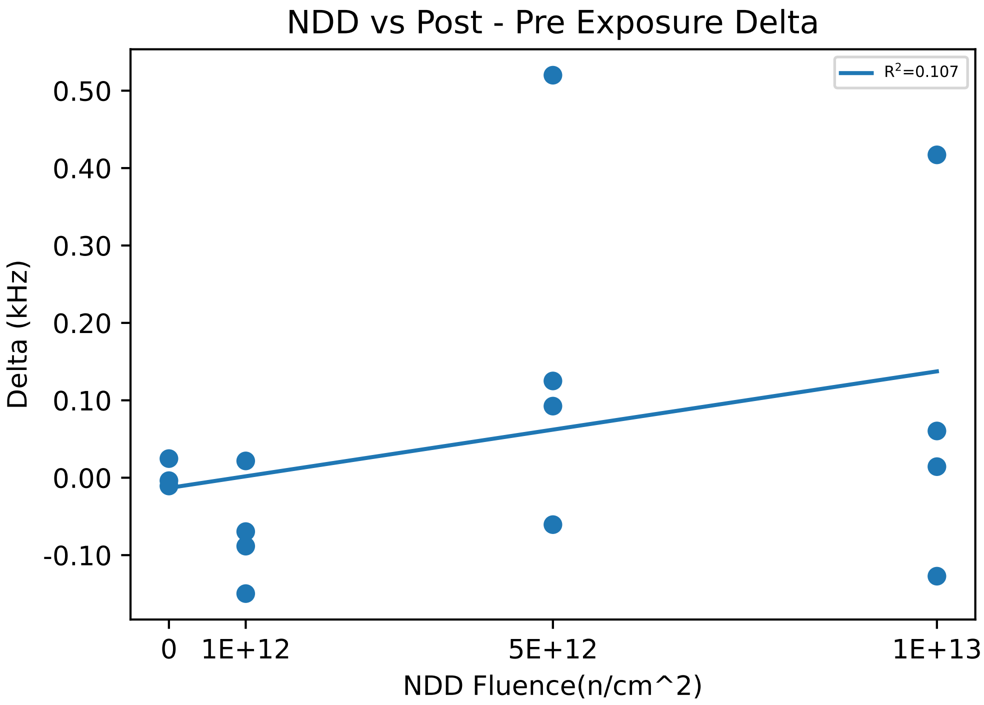
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200	199.99	-0.012
2	1e+12	NDD	200.01	200	-0.0109
3	1e+12	NDD	200.01	200	-0.0044
4	1e+12	NDD	200	200	-0.0079
5	5e+12	NDD	200.01	200	-0.0112
6	5e+12	NDD	200.01	200	-0.0057
7	5e+12	NDD	200	199.94	-0.0589
8	5e+12	NDD	200	200	-0.0054
9	1e+13	NDD	200.01	200	-0.013
10	1e+13	NDD	200	199.99	-0.0118
11	1e+13	NDD	200.01	200	-0.0163
12	1e+13	NDD	200.01	200	-0.0062
13	0	CORRELATION	200	200	-0.0063
14	0	CORRELATION	200	200	-0.0082
15	0	CORRELATION	200.01	200	-0.007

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200.01	200.01	0.003365	200	200	200	0.0034871	-0.0082	-0.0071667	-0.0063	0.0009609
1e+12	200	200.01	200.01	0.0045768	199.99	200	200	0.0056445	-0.012	-0.0088	-0.0044	0.0034069
5e+12	200	200	200.01	0.0035415	199.94	199.98	200	0.028263	-0.0589	-0.0203	-0.0054	0.025871
1e+13	200	200.01	200.01	0.0041833	199.99	200	200	0.0047836	-0.0163	-0.011825	-0.0062	0.0042051

Device Test: 20.35 LEVEL|FREQ/RT/12/12/0/0/5/200kHz//@FSW_EXT_RT_B





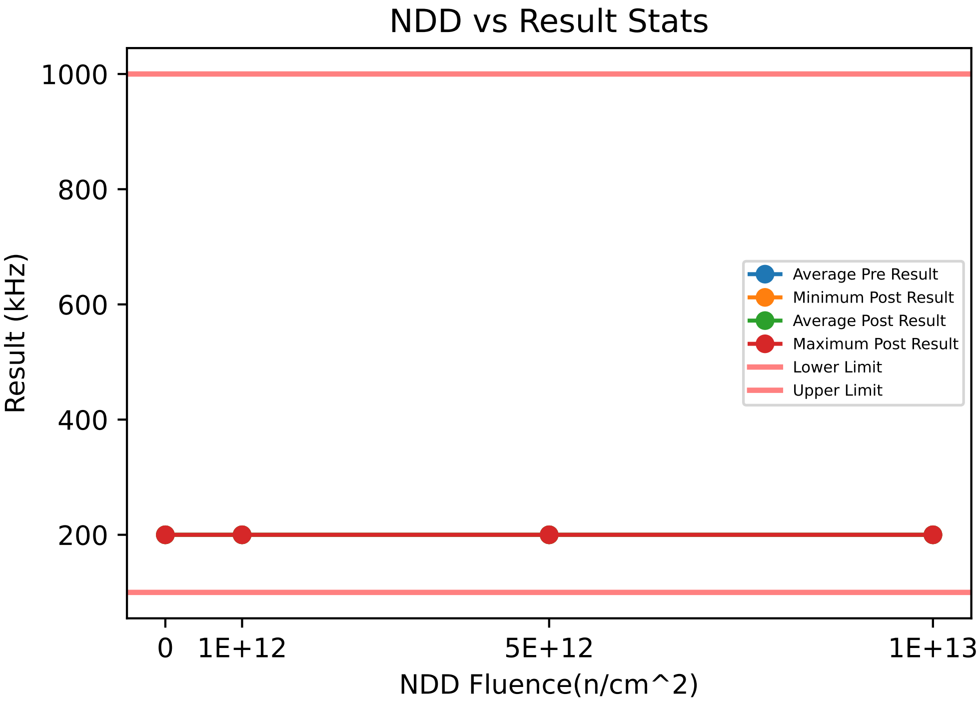
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

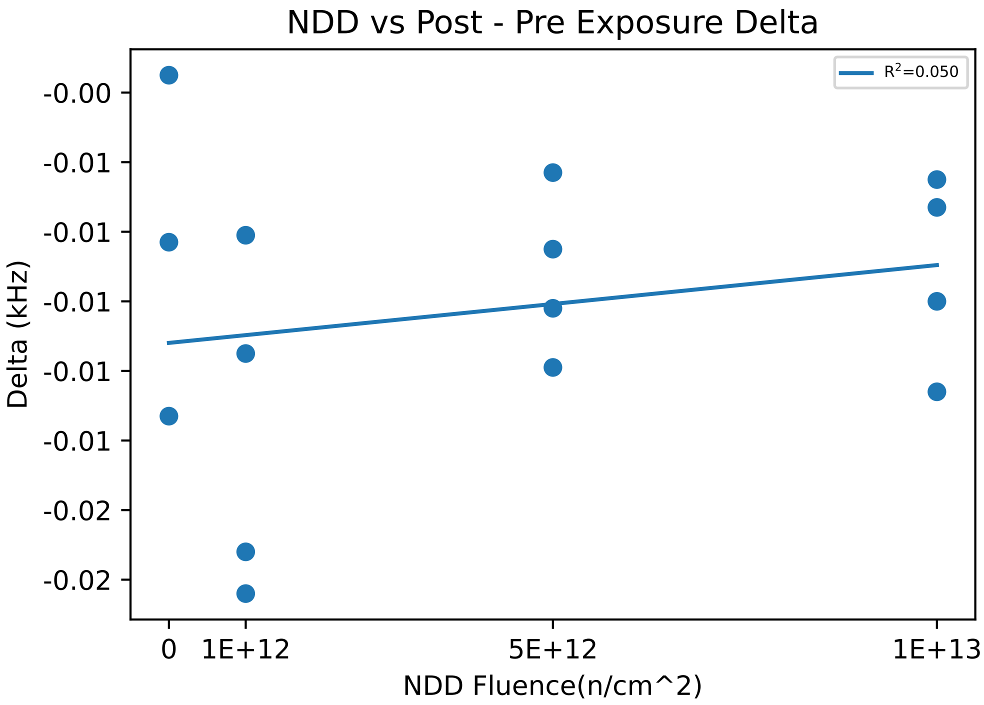
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.22	197.15	-0.0696
2	1e+12	NDD	193.52	193.43	-0.0884
3	1e+12	NDD	194.52	194.54	0.0217
4	1e+12	NDD	195.53	195.38	-0.1497
5	5e+12	NDD	188.29	188.41	0.125
6	5e+12	NDD	192.87	192.96	0.0925
7	5e+12	NDD	197.66	198.18	0.52
8	5e+12	NDD	198.82	198.76	-0.0606
9	1e+13	NDD	197.48	197.9	0.4171
10	1e+13	NDD	197.66	197.72	0.0604
11	1e+13	NDD	199.33	199.2	-0.1272
12	1e+13	NDD	196.88	196.9	0.0143
13	0	CORRELATION	194.24	194.27	0.0247
14	0	CORRELATION	197.37	197.36	-0.0038
15	0	CORRELATION	192.6	192.59	-0.0107

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.6	194.74	197.37	2.4234	192.59	194.74	197.36	2.4236	-0.0107	0.0034	0.0247	0.018766
1e+12	193.52	195.2	197.22	1.58	193.43	195.13	197.15	1.5696	-0.1497	-0.0715	0.0217	0.070924
5e+12	188.29	194.41	198.82	4.825	188.41	194.58	198.76	4.8667	-0.0606	0.16922	0.52	0.24746
1e+13	196.88	197.84	199.33	1.0478	196.9	197.93	199.2	0.95336	-0.1272	0.09115	0.4171	0.2315

Device Test: 20.36 LEVEL|FREQ/SYNC/12/12/0/0/5/200kHz//@FREQ_SYNC_EXT





Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

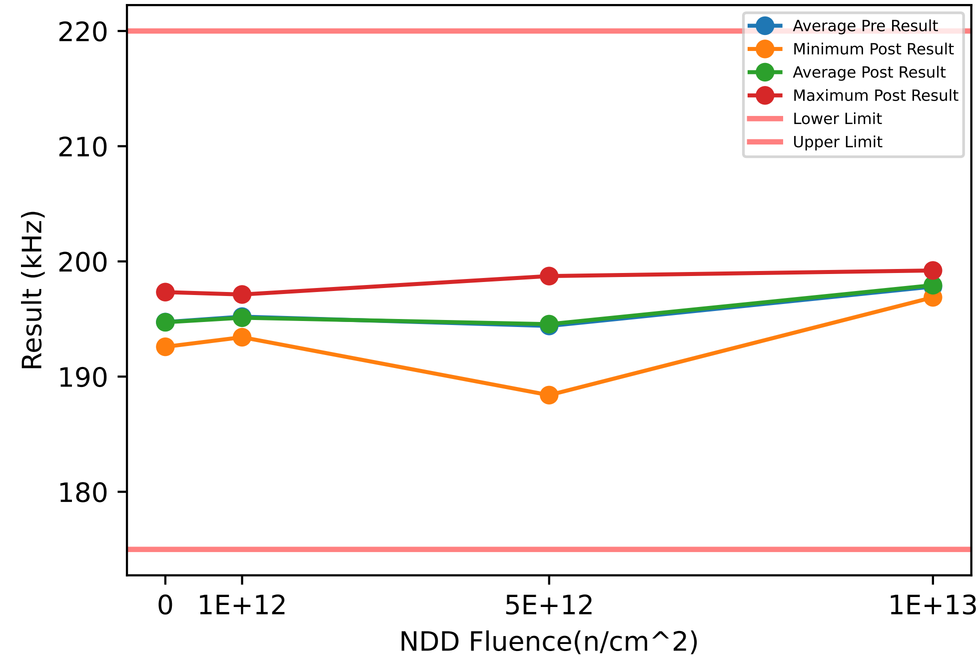
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200	200	-0.0081
2	1e+12	NDD	200.01	200	-0.0172
3	1e+12	NDD	200.01	200	-0.0115
4	1e+12	NDD	200.01	199.99	-0.0184
5	5e+12	NDD	200.01	200	-0.0063
6	5e+12	NDD	200.01	200	-0.0102
7	5e+12	NDD	200	200	-0.0085
8	5e+12	NDD	200.01	200	-0.0119
9	1e+13	NDD	200.01	200	-0.0126
10	1e+13	NDD	200	200	-0.0065
11	1e+13	NDD	200.01	200	-0.0073
12	1e+13	NDD	200.01	200	-0.01
13	0	CORRELATION	200.01	200	-0.0133
14	0	CORRELATION	200	200	-0.0035
15	0	CORRELATION	200.01	200	-0.0083

Test Statistics (kHz)

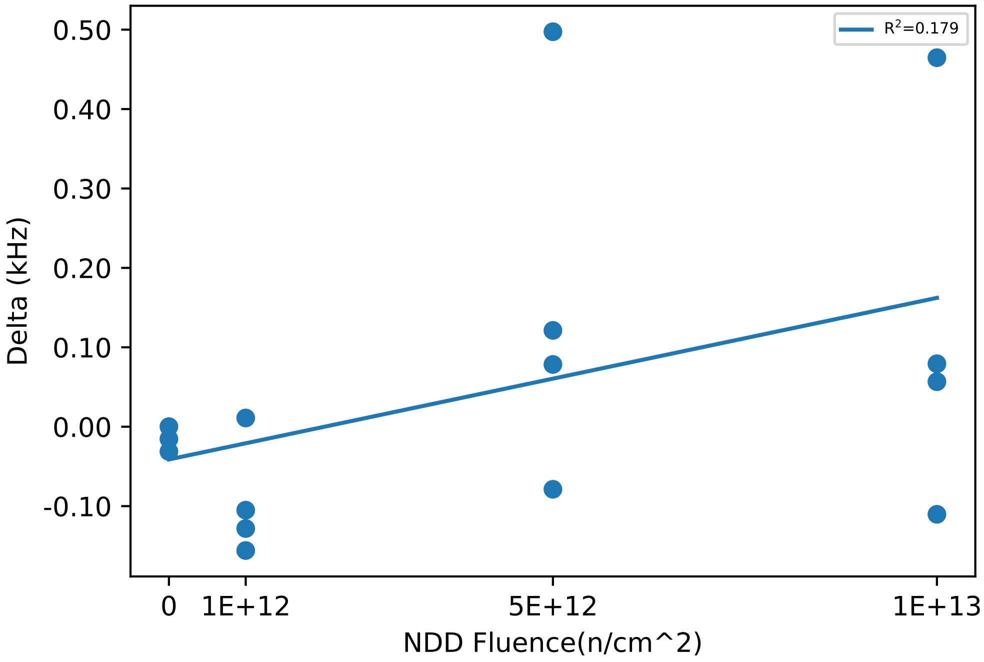
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200.01	200.01	0.0026153	200	200	200	0.0032332	-0.0133	-0.0083667	-0.0035	0.0049003
1e+12	200	200.01	200.01	0.0035538	199.99	199.99	200	0.003357	-0.0184	-0.0138	-0.0081	0.0048477
5e+12	200	200.01	200.01	0.0032816	200	200	200	0.0038179	-0.0119	-0.009225	-0.0063	0.0023936
1e+13	200	200.01	200.01	0.0036317	200	200	200	0.002917	-0.0126	-0.0091	-0.0065	0.0027725

Device Test: 20.37 LEVEL|FREQ/RT/14/14/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



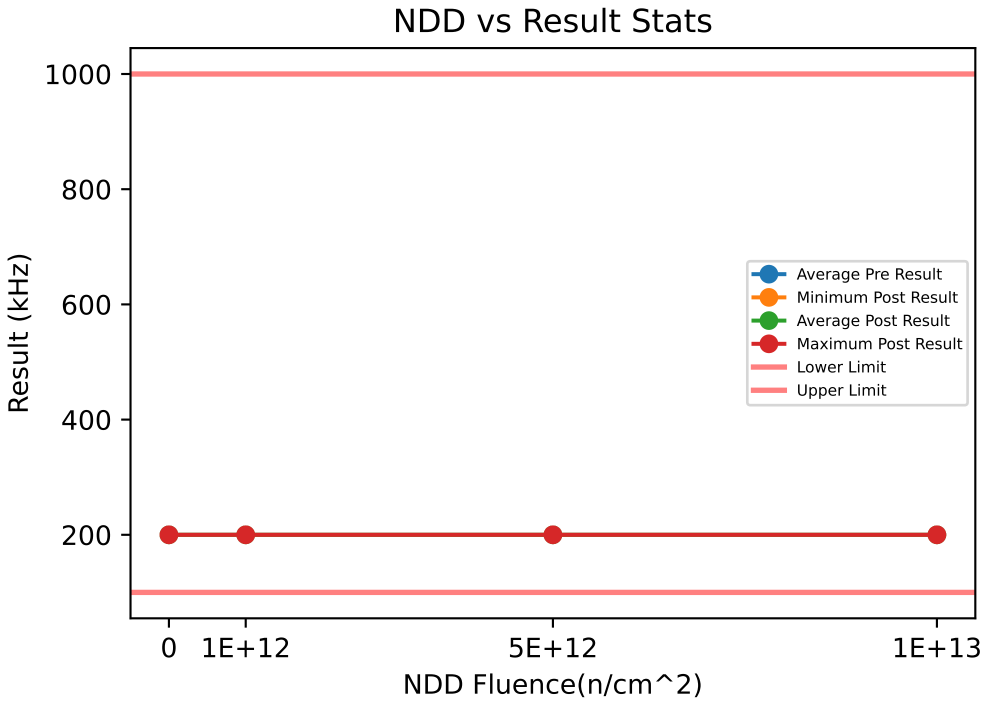
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

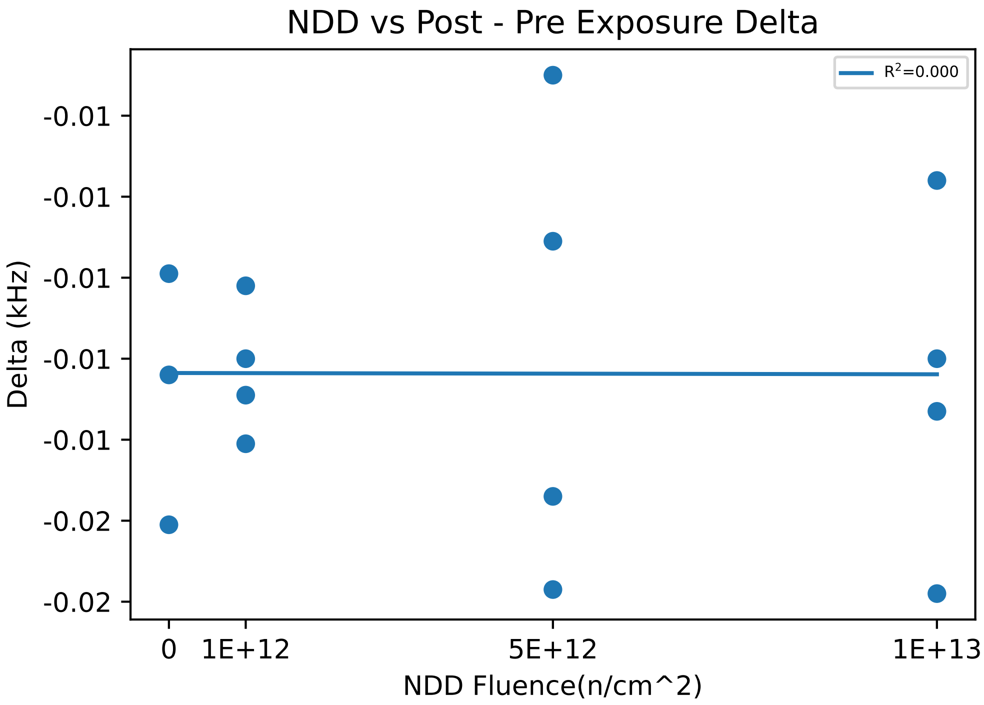
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.23	197.13	-0.1051
2	1e+12	NDD	193.55	193.42	-0.1282
3	1e+12	NDD	194.53	194.54	0.011
4	1e+12	NDD	195.51	195.36	-0.1559
5	5e+12	NDD	188.27	188.39	0.1213
6	5e+12	NDD	192.87	192.95	0.0784
7	5e+12	NDD	197.64	198.13	0.4974
8	5e+12	NDD	198.81	198.73	-0.0788
9	1e+13	NDD	197.46	197.92	0.4647
10	1e+13	NDD	197.64	197.71	0.0793
11	1e+13	NDD	199.32	199.21	-0.1103
12	1e+13	NDD	196.82	196.88	0.0567
13	0	CORRELATION	194.23	194.23	0.0001
14	0	CORRELATION	197.35	197.33	-0.0154
15	0	CORRELATION	192.62	192.59	-0.0312

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.62	194.73	197.35	2.4055	192.59	194.72	197.33	2.4109	-0.0312	-0.0155	0.0001	0.01565
1e+12	193.55	195.21	197.23	1.5722	193.42	195.11	197.13	1.562	-0.1559	-0.09455	0.011	0.073367
5e+12	188.27	194.4	198.81	4.8226	188.39	194.55	198.73	4.8564	-0.0788	0.15458	0.4974	0.2442
1e+13	196.82	197.81	199.32	1.0668	196.88	197.93	199.21	0.96449	-0.1103	0.1226	0.4647	0.24324

Device Test: 20.38 LEVEL|FREQ/SYNC/14/14/0/0/5/200kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

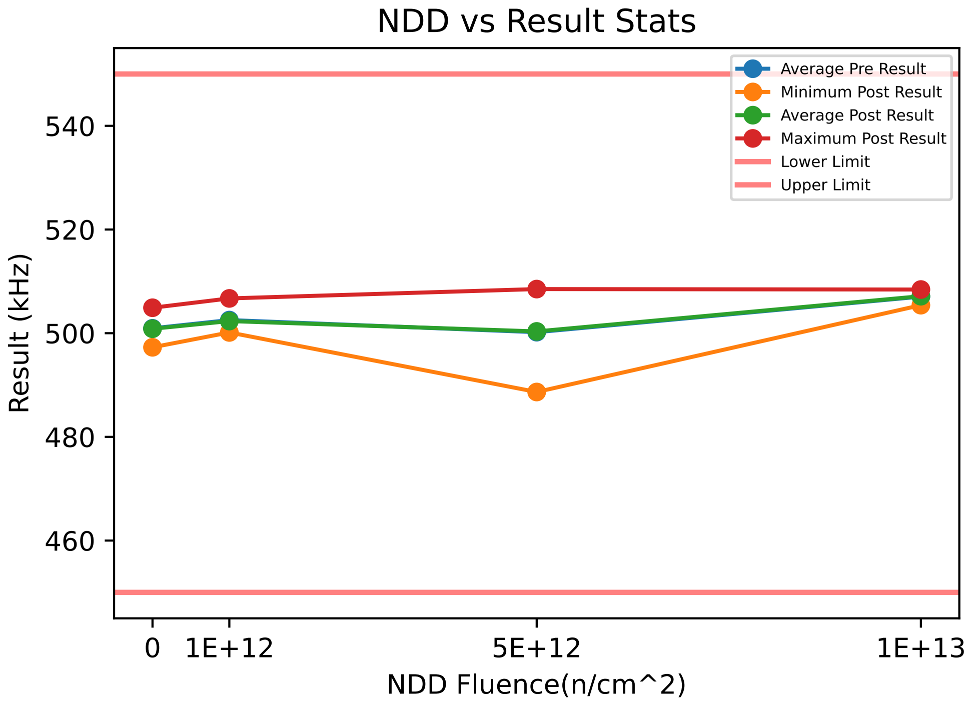
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

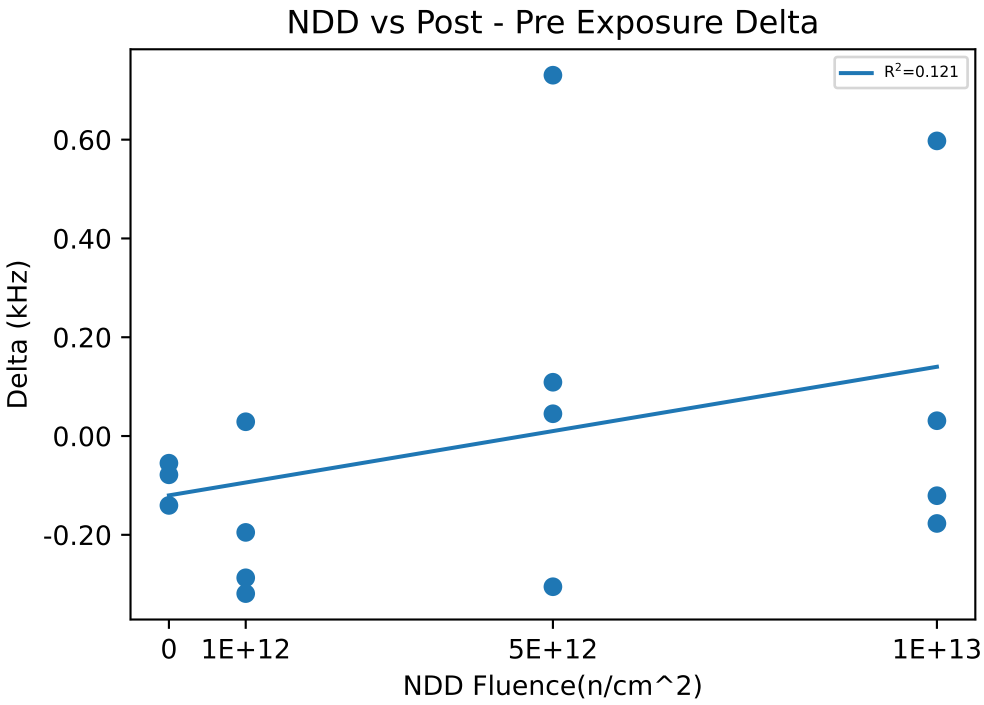
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200.01	200	-0.0141
2	1e+12	NDD	200.01	200	-0.0129
3	1e+12	NDD	200.01	200	-0.0102
4	1e+12	NDD	200.01	200	-0.012
5	5e+12	NDD	200.01	200	-0.0154
6	5e+12	NDD	200.01	200	-0.0177
7	5e+12	NDD	200	199.99	-0.0091
8	5e+12	NDD	200.01	200	-0.005
9	1e+13	NDD	200.01	200	-0.0076
10	1e+13	NDD	200.01	200	-0.0133
11	1e+13	NDD	200.01	200	-0.0178
12	1e+13	NDD	200.01	200	-0.012
13	0	CORRELATION	200	199.99	-0.0124
14	0	CORRELATION	200	199.99	-0.0099
15	0	CORRELATION	200.01	200	-0.0161

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200.01	200.01	0.0050895	199.99	199.99	200	0.0033724	-0.0161	-0.0128	-0.0099	0.0031193
1e+12	200.01	200.01	200.01	0.0019157	200	200	200	0.0032047	-0.0141	-0.0123	-0.0102	0.0016432
5e+12	200	200.01	200.01	0.0046928	199.99	200	200	0.0032325	-0.0177	-0.0118	-0.005	0.0058109
1e+13	200.01	200.01	200.01	0.0019466	200	200	200	0.0030293	-0.0178	-0.012675	-0.0076	0.0041979

Device Test: 20.39 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/500kHz//@FSW_EXT_RT_C





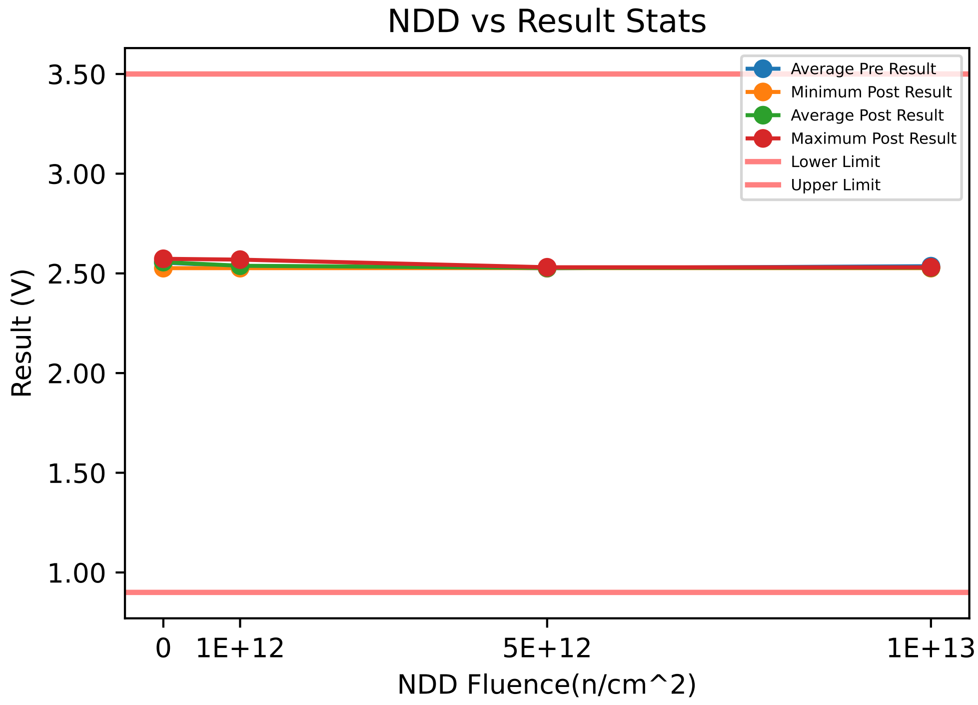
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

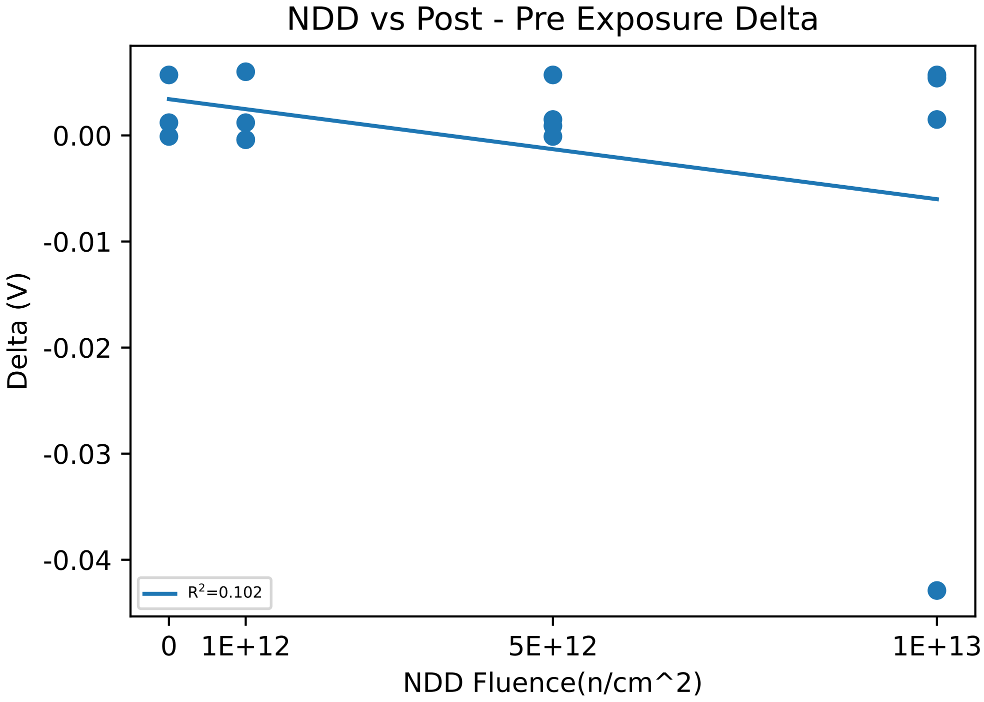
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	506.91	506.71	-0.1951
2	1e+12	NDD	500.43	500.15	-0.287
3	1e+12	NDD	500.22	500.25	0.0289
4	1e+12	NDD	502.57	502.25	-0.319
5	5e+12	NDD	488.61	488.66	0.0451
6	5e+12	NDD	498.32	498.43	0.1089
7	5e+12	NDD	505.04	505.77	0.7305
8	5e+12	NDD	508.82	508.51	-0.3051
9	1e+13	NDD	507.11	507.71	0.5975
10	1e+13	NDD	507.13	507.01	-0.1208
11	1e+13	NDD	508.6	508.42	-0.177
12	1e+13	NDD	505.38	505.41	0.031
13	0	CORRELATION	500.42	500.37	-0.055
14	0	CORRELATION	504.99	504.91	-0.0785
15	0	CORRELATION	497.42	497.28	-0.1405

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	497.42	500.94	504.99	3.8098	497.28	500.85	504.91	3.837	-0.1405	-0.091333	-0.055	0.044171
1e+12	500.22	502.53	506.91	3.103	500.15	502.34	506.71	3.0714	-0.319	-0.19305	0.0289	0.15701
5e+12	488.61	500.2	508.82	8.8607	488.66	500.34	508.51	8.878	-0.3051	0.14485	0.7305	0.43077
1e+13	505.38	507.05	508.6	1.3192	505.41	507.14	508.42	1.2908	-0.177	0.082675	0.5975	0.35428

Device Test: 20.4 LEVEL|HIGH_LEVEL/SYNC/4.8/4.8/0/0/4.5/500kHz//@SYNC_VIH_TH_LOW_4P5





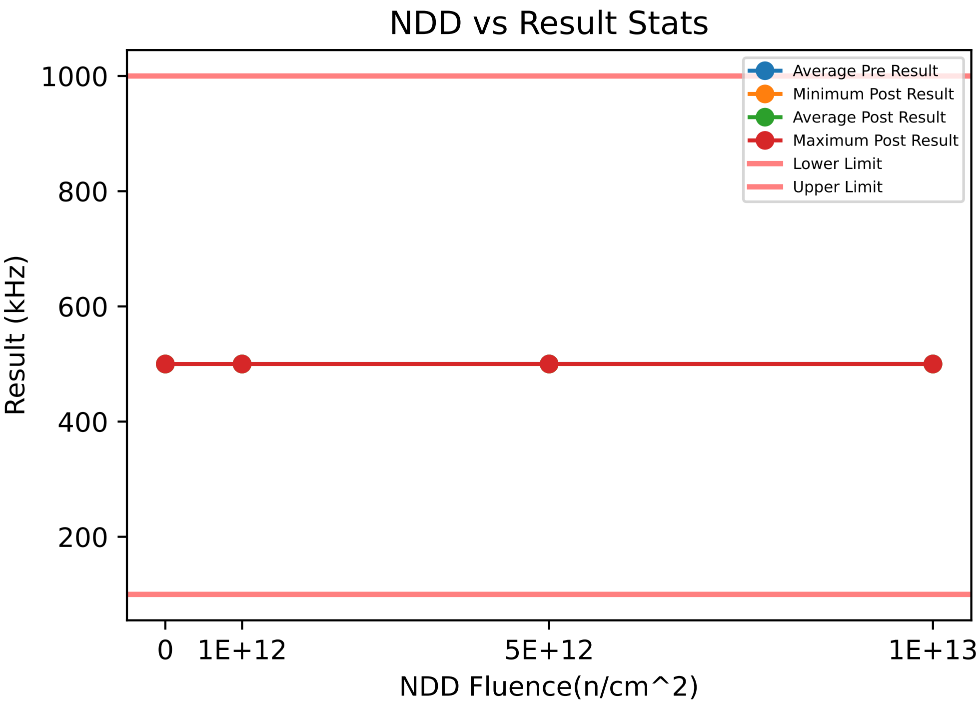
Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

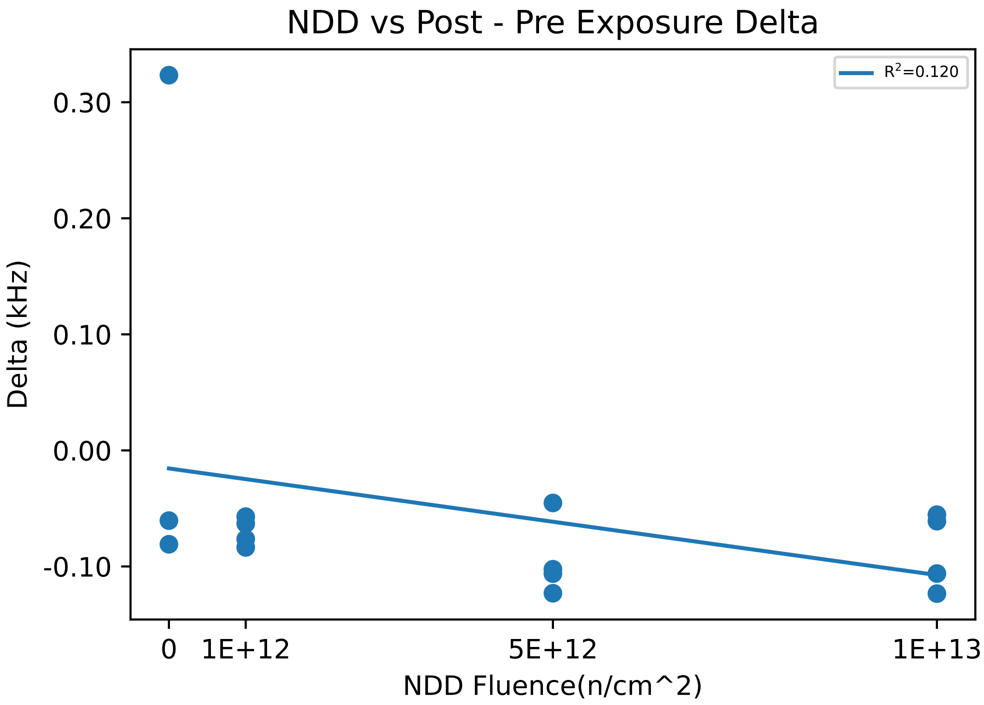
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.5694	2.569	-0.0004
2	1e+12	NDD	2.5257	2.5269	0.0012
3	1e+12	NDD	2.5247	2.5307	0.006
4	1e+12	NDD	2.5266	2.5262	-0.0004
5	5e+12	NDD	2.526	2.5269	0.0009
6	5e+12	NDD	2.525	2.5307	0.0057
7	5e+12	NDD	2.5266	2.5265	-0.0001
8	5e+12	NDD	2.5257	2.5272	0.0015
9	1e+13	NDD	2.5247	2.5304	0.0057
10	1e+13	NDD	2.5691	2.5262	-0.0429
11	1e+13	NDD	2.5257	2.5272	0.0015
12	1e+13	NDD	2.525	2.5304	0.0054
13	0	CORRELATION	2.5263	2.5262	-0.0001
14	0	CORRELATION	2.5688	2.57	0.0012
15	0	CORRELATION	2.5675	2.5732	0.0057

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5263	2.5542	2.5688	0.024171	2.5262	2.5565	2.5732	0.02626	-0.0001	0.0022667	0.0057	0.0030436
1e+12	2.5247	2.5366	2.5694	0.02188	2.5262	2.5382	2.569	0.020628	-0.0004	0.0016	0.006	0.0030288
5e+12	2.525	2.5258	2.5266	0.00066521	2.5265	2.5278	2.5307	0.001938	-0.0001	0.002	0.0057	0.0025534
1e+13	2.5247	2.5361	2.5691	0.021987	2.5262	2.5286	2.5304	0.0021749	-0.0429	-0.007575	0.0057	0.023628

Device Test: 20.40 LEVEL|FREQ/SYNC/4.5/4.5/0/0/4.5/500kHz//@FREQ_SYNC_EXT





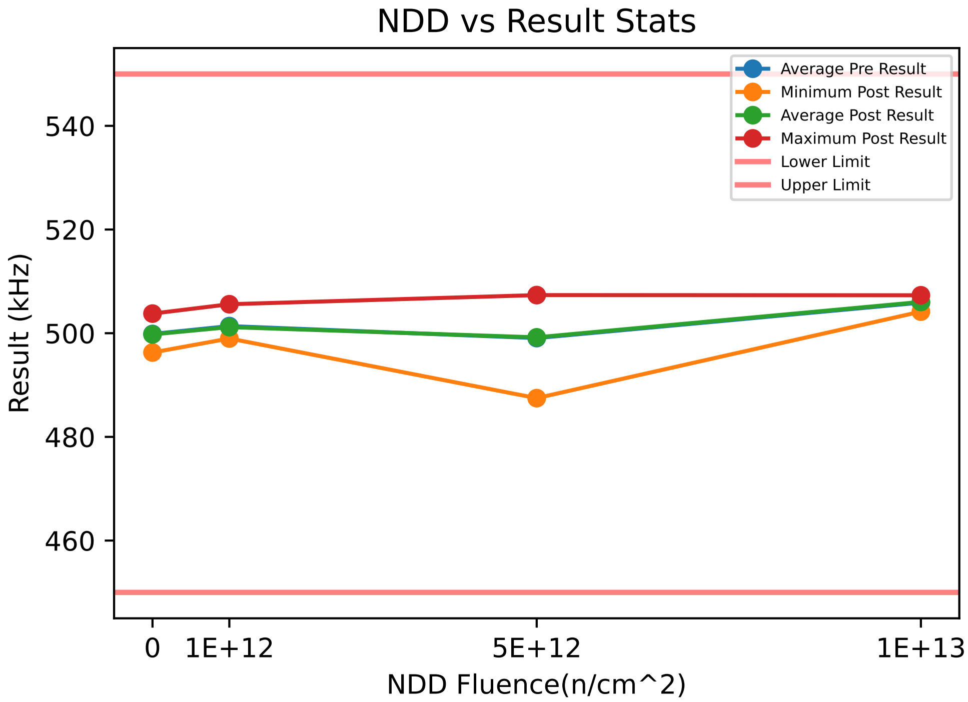
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

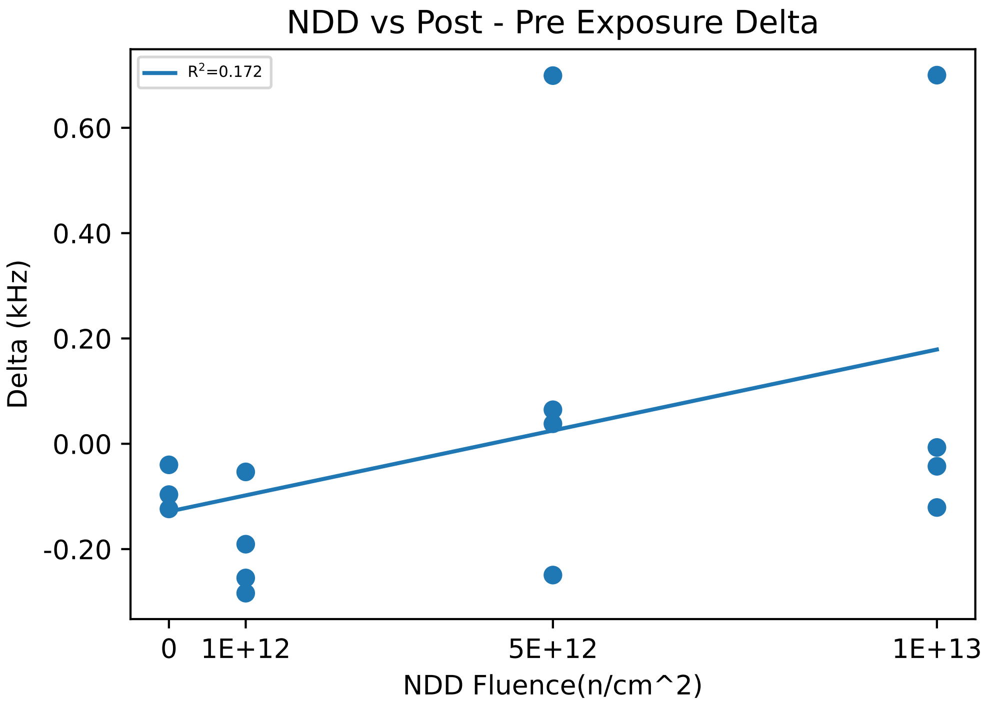
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.04	499.98	-0.0571
2	1e+12	NDD	500.05	499.97	-0.0764
3	1e+12	NDD	500.06	499.98	-0.0836
4	1e+12	NDD	500.04	499.98	-0.0631
5	5e+12	NDD	500.08	499.97	-0.1062
6	5e+12	NDD	500.07	499.97	-0.1024
7	5e+12	NDD	500.06	499.94	-0.1231
8	5e+12	NDD	500.07	500.02	-0.0453
9	1e+13	NDD	500.08	499.98	-0.1061
10	1e+13	NDD	500.06	499.94	-0.1234
11	1e+13	NDD	500.08	500.02	-0.0554
12	1e+13	NDD	500.04	499.98	-0.061
13	0	CORRELATION	500.06	499.98	-0.0809
14	0	CORRELATION	500.08	500.02	-0.0605
15	0	CORRELATION	499.64	499.97	0.3233

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.64	499.93	500.08	0.24435	499.97	499.99	500.02	0.025893	-0.0809	0.060633	0.3233	0.2277
1e+12	500.04	500.05	500.06	0.010696	499.97	499.98	499.98	0.0037313	-0.0836	-0.07005	-0.0571	0.01211
5e+12	500.06	500.07	500.08	0.0070612	499.94	499.98	500.02	0.034588	-0.1231	-0.09425	-0.0453	0.033851
1e+13	500.04	500.07	500.08	0.018723	499.94	499.98	500.02	0.034813	-0.1234	-0.086475	-0.0554	0.033482

Device Test: 20.43 LEVEL|FREQ/RT/5/5/0/0/5/500kHz//@FSW_EXT_RT_C





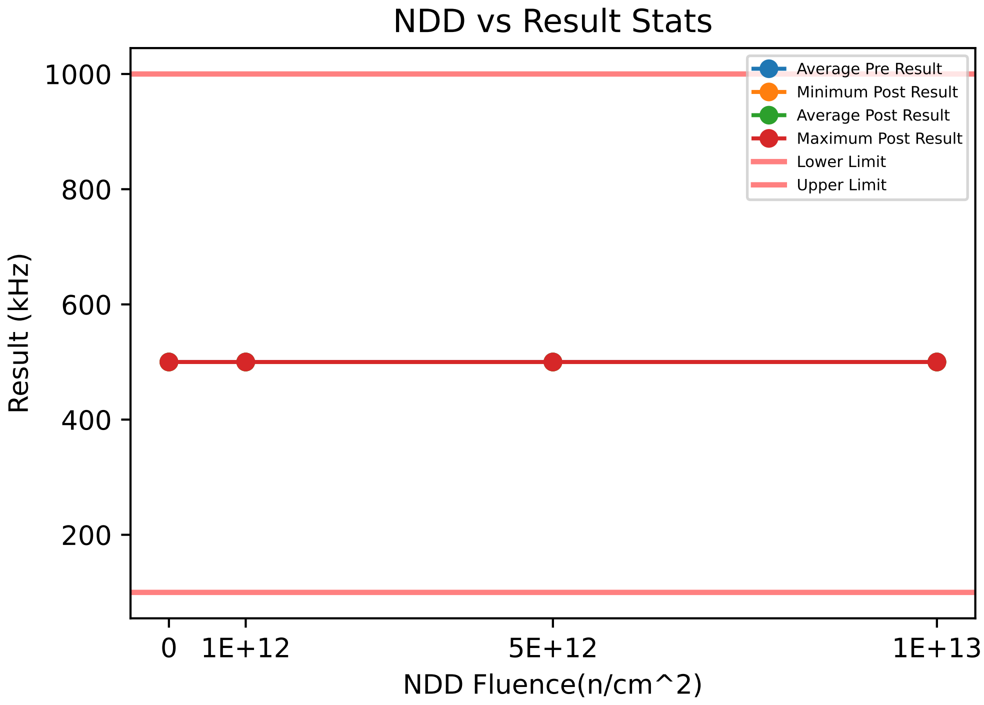
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

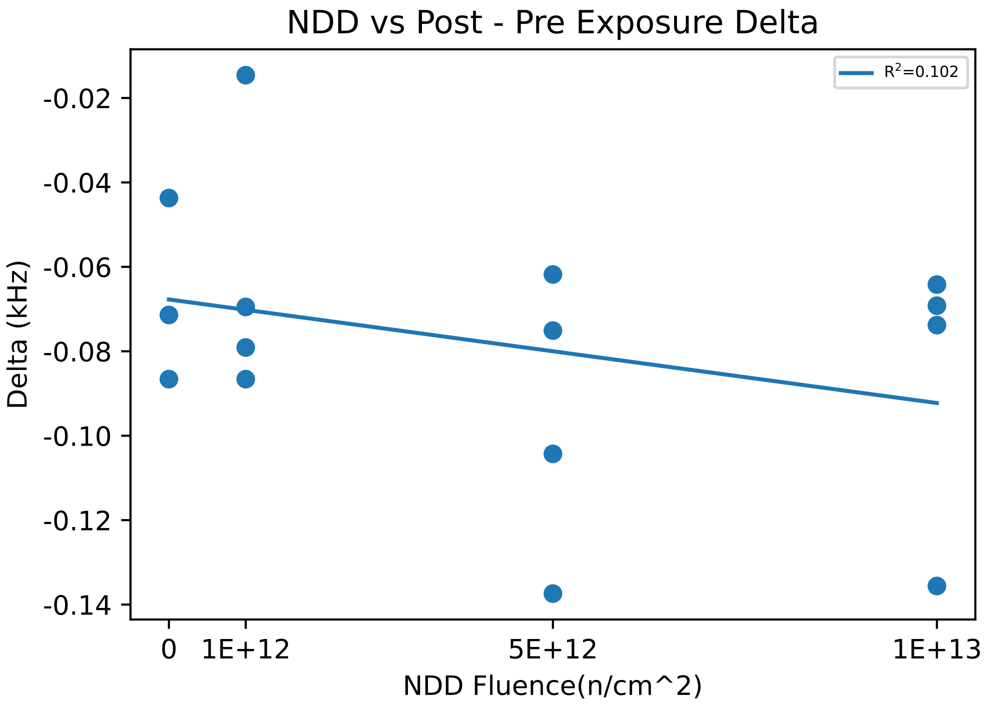
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.84	505.59	-0.2548
2	1e+12	NDD	499.17	498.98	-0.1907
3	1e+12	NDD	499.13	499.08	-0.0534
4	1e+12	NDD	501.33	501.05	-0.2837
5	5e+12	NDD	487.43	487.47	0.038
6	5e+12	NDD	497.2	497.26	0.0646
7	5e+12	NDD	504.01	504.71	0.6991
8	5e+12	NDD	507.6	507.35	-0.2493
9	1e+13	NDD	505.96	506.66	0.7
10	1e+13	NDD	506.03	505.99	-0.0428
11	1e+13	NDD	507.44	507.32	-0.121
12	1e+13	NDD	504.17	504.16	-0.007
13	0	CORRELATION	499.37	499.24	-0.1237
14	0	CORRELATION	503.82	503.78	-0.04
15	0	CORRELATION	496.37	496.27	-0.0965

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.37	499.85	503.82	3.7488	496.27	499.77	503.78	3.7806	-0.1237	-0.086733	-0.04	0.042696
1e+12	499.13	501.37	505.84	3.1544	498.98	501.17	505.59	3.0931	-0.2837	-0.19565	-0.0534	0.10249
5e+12	487.43	499.06	507.6	8.8698	487.47	499.2	507.35	8.9077	-0.2493	0.1381	0.6991	0.40009
1e+13	504.17	505.9	507.44	1.3381	504.16	506.03	507.32	1.358	-0.121	0.1323	0.7	0.38145

Device Test: 20.44 LEVEL|FREQ/SYNC/5/5/0/0/5/500kHz//@FREQ_SYNC_EXT





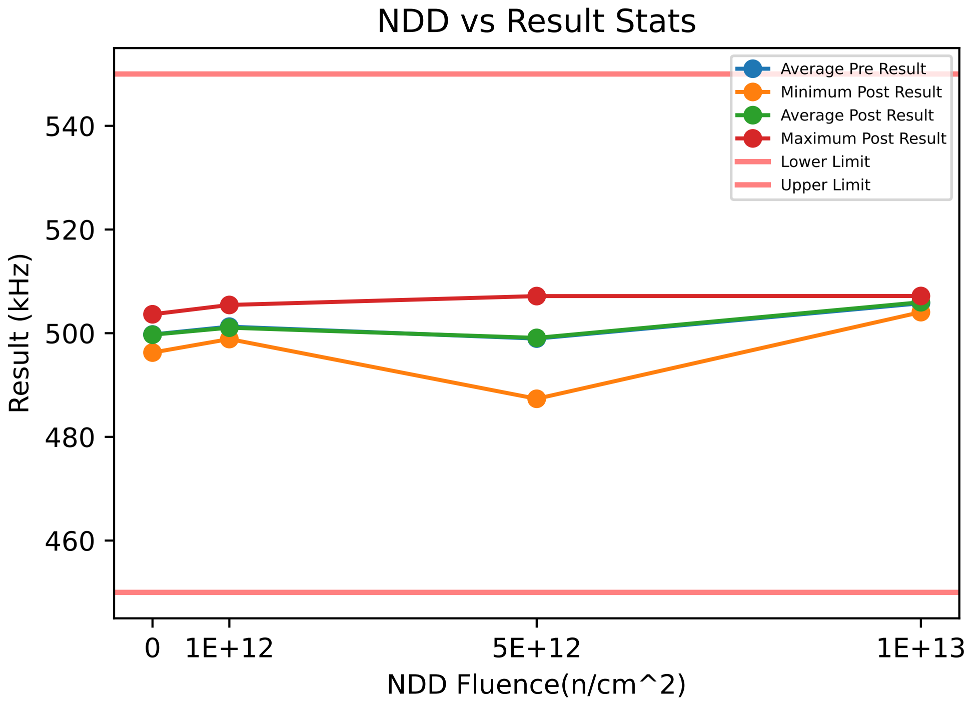
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

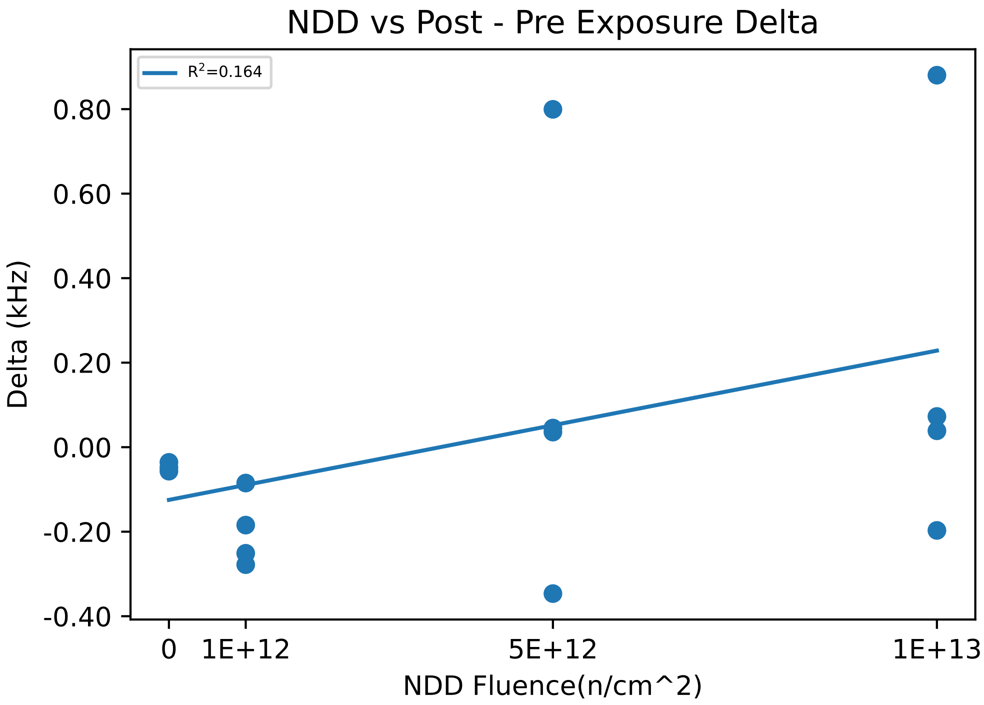
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.02	499.94	-0.0791
2	1e+12	NDD	500.03	500.01	-0.0146
3	1e+12	NDD	500.05	499.98	-0.0695
4	1e+12	NDD	500.03	499.94	-0.0866
5	5e+12	NDD	500.07	500.01	-0.0618
6	5e+12	NDD	500.12	499.98	-0.1374
7	5e+12	NDD	500.01	499.94	-0.0751
8	5e+12	NDD	500.07	499.96	-0.1043
9	1e+13	NDD	500.11	499.98	-0.1356
10	1e+13	NDD	500.05	499.98	-0.0738
11	1e+13	NDD	500.03	499.97	-0.0642
12	1e+13	NDD	500.08	500.01	-0.0692
13	0	CORRELATION	500.02	499.98	-0.0437
14	0	CORRELATION	500.09	500.01	-0.0714
15	0	CORRELATION	500.1	500.01	-0.0866

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.02	500.07	500.1	0.040608	499.98	500	500.01	0.019713	-0.0866	-0.067233	-0.0437	0.021751
1e+12	500.02	500.03	500.05	0.013052	499.94	499.97	500.01	0.034918	-0.0866	-0.06245	-0.0146	0.032659
5e+12	500.01	500.07	500.12	0.043067	499.94	499.97	500.01	0.030841	-0.1374	-0.09465	-0.0618	0.033576
1e+13	500.03	500.07	500.11	0.035585	499.97	499.98	500.01	0.020154	-0.1356	-0.0857	-0.0642	0.033497

Device Test: 20.47 LEVEL|FREQ/RT/12/12/0/0/5/500kHz//@FSW_EXT_RT_C





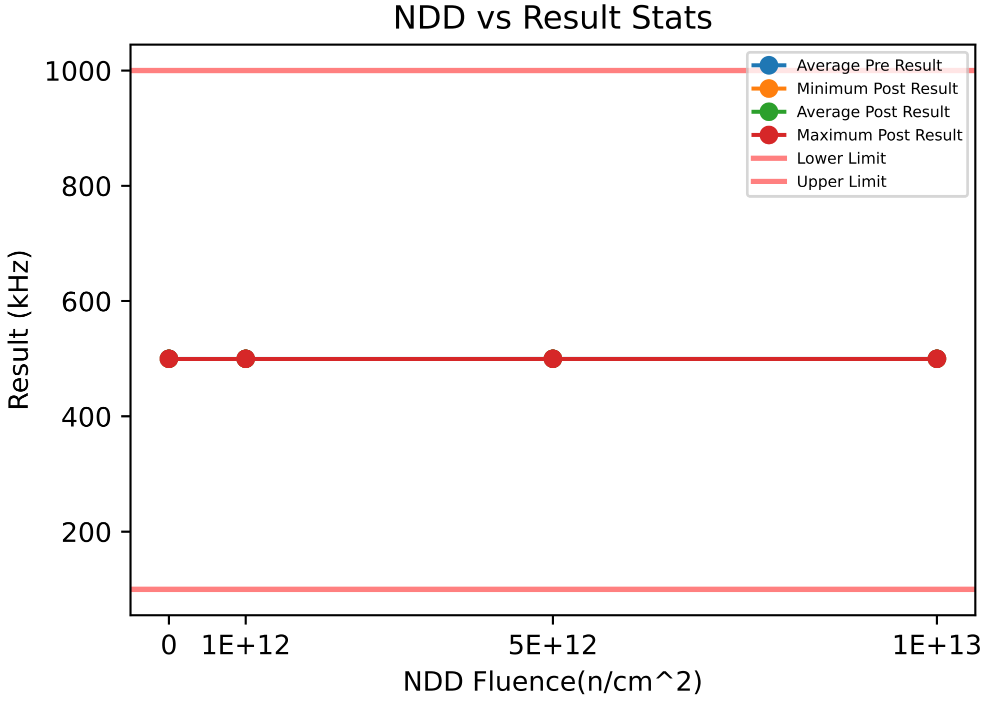
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

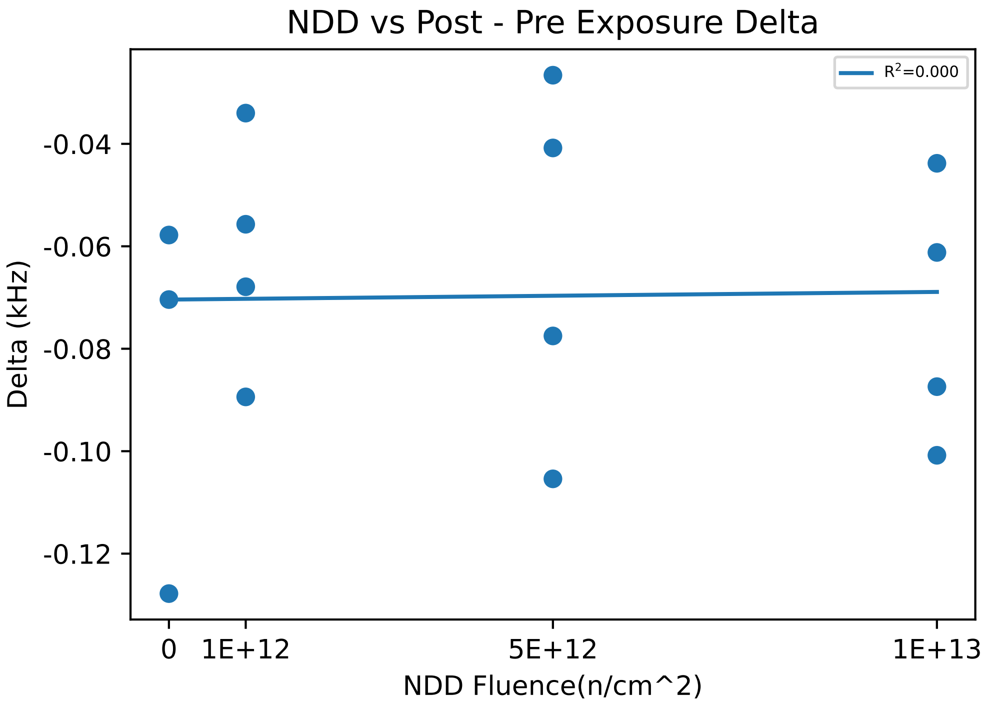
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.7	505.45	-0.2511
2	1e+12	NDD	499.06	498.87	-0.1844
3	1e+12	NDD	499.06	498.97	-0.0849
4	1e+12	NDD	501.24	500.96	-0.278
5	5e+12	NDD	487.3	487.35	0.0453
6	5e+12	NDD	497.1	497.14	0.0357
7	5e+12	NDD	503.93	504.73	0.7995
8	5e+12	NDD	507.51	507.16	-0.3465
9	1e+13	NDD	505.81	506.69	0.8803
10	1e+13	NDD	505.89	505.97	0.0727
11	1e+13	NDD	507.37	507.17	-0.197
12	1e+13	NDD	504.02	504.06	0.0388
13	0	CORRELATION	499.24	499.21	-0.0359
14	0	CORRELATION	503.7	503.65	-0.0482
15	0	CORRELATION	496.32	496.26	-0.0568

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.32	499.75	503.7	3.7144	496.26	499.71	503.65	3.7175	-0.0568	-0.046967	-0.0359	0.010504
1e+12	499.06	501.26	505.7	3.1307	498.87	501.06	505.45	3.0767	-0.278	-0.1996	-0.0849	0.085996
5e+12	487.3	498.96	507.51	8.8903	487.35	499.09	507.16	8.919	-0.3465	0.1335	0.7995	0.48003
1e+13	504.02	505.77	507.37	1.3703	504.06	505.97	507.17	1.3668	-0.197	0.1987	0.8803	0.46996

Device Test: 20.48 LEVEL|FREQ/SYNC/12/12/0/0/5/500kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

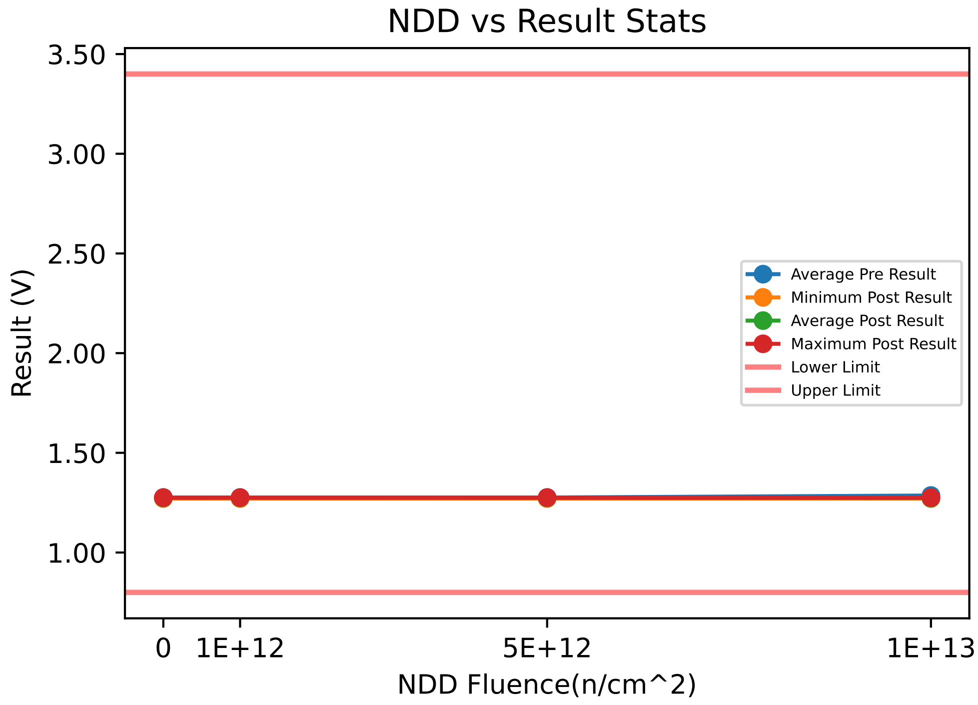
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

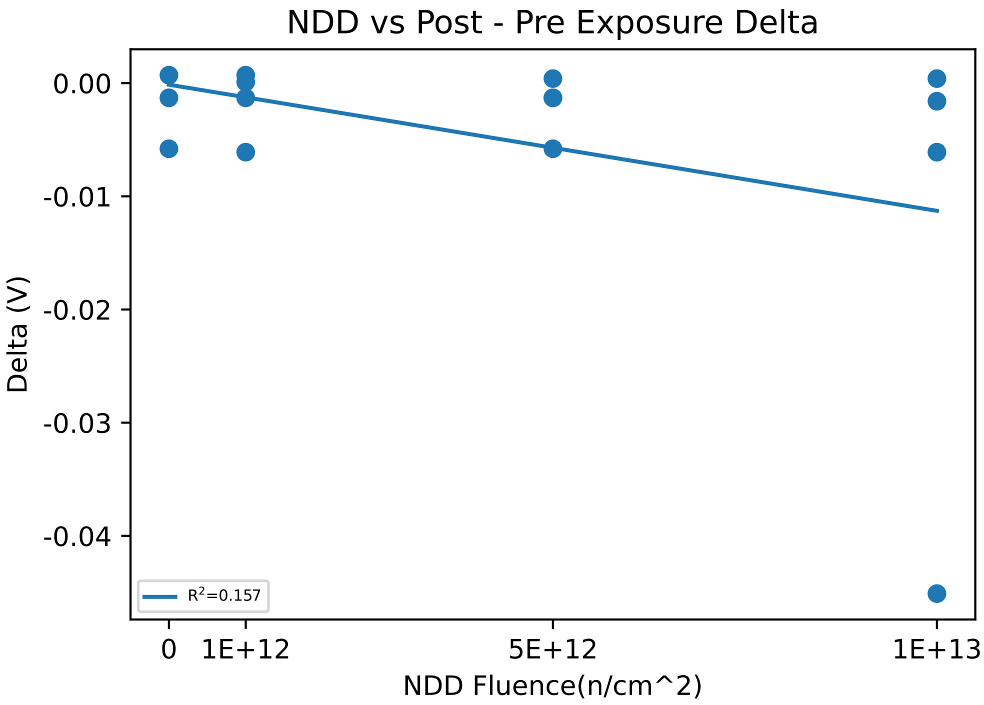
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.01	499.98	-0.034
2	1e+12	NDD	500.07	499.98	-0.0894
3	1e+12	NDD	500.04	499.98	-0.0679
4	1e+12	NDD	500.03	499.97	-0.0557
5	5e+12	NDD	500.08	500	-0.0775
6	5e+12	NDD	500.12	500.01	-0.1054
7	5e+12	NDD	500.02	499.98	-0.0408
8	5e+12	NDD	500.03	500	-0.0266
9	1e+13	NDD	500.04	499.98	-0.0612
10	1e+13	NDD	500.03	499.94	-0.0874
11	1e+13	NDD	500.08	499.97	-0.1008
12	1e+13	NDD	500.06	500.01	-0.0438
13	0	CORRELATION	500.06	499.93	-0.1278
14	0	CORRELATION	500.03	499.97	-0.0578
15	0	CORRELATION	500.05	499.97	-0.0704

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.03	500.04	500.06	0.014354	499.93	499.96	499.97	0.024535	-0.1278	-0.085333	-0.0578	0.037313
1e+12	500.01	500.04	500.07	0.023419	499.97	499.98	499.98	0.0022911	-0.0894	-0.06175	-0.034	0.023159
5e+12	500.02	500.06	500.12	0.045906	499.98	500	500.01	0.015217	-0.1054	-0.062575	-0.0266	0.035708
1e+13	500.03	500.05	500.08	0.020714	499.94	499.98	500.01	0.029965	-0.1008	-0.0733	-0.0438	0.025637

Device Test: 20.5 LEVEL|LOW_LEVEL/SYNC/5/5/0/0/4.5/500kHz//@SYNC_VIL_TH_HIGH_4P5





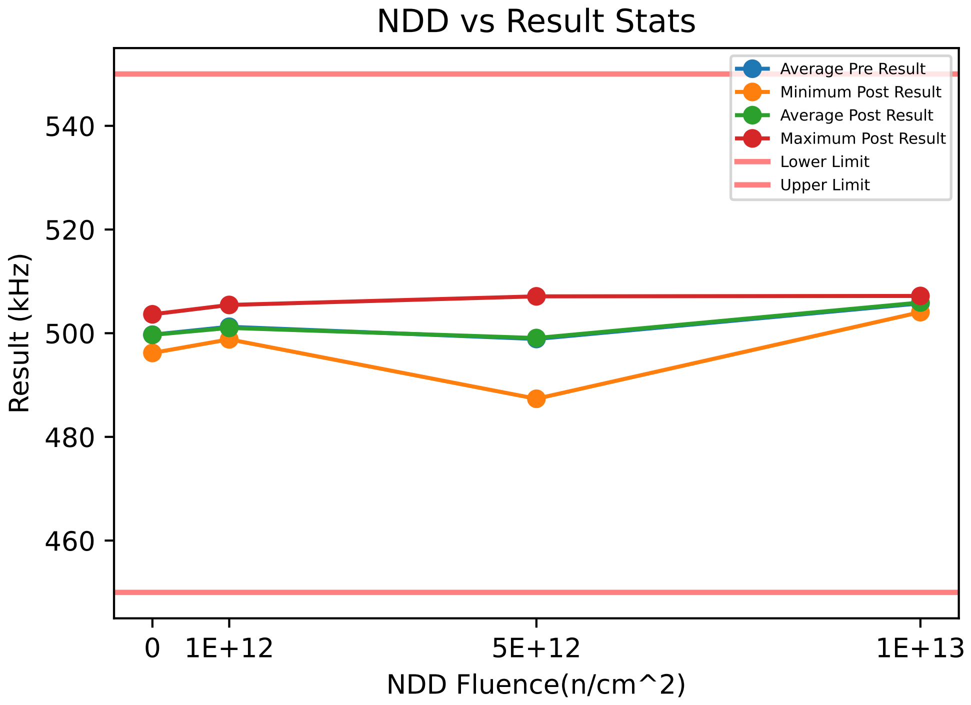
Test Results (Lower Limit = 0.8, Upper Limit = 3.4 (V))

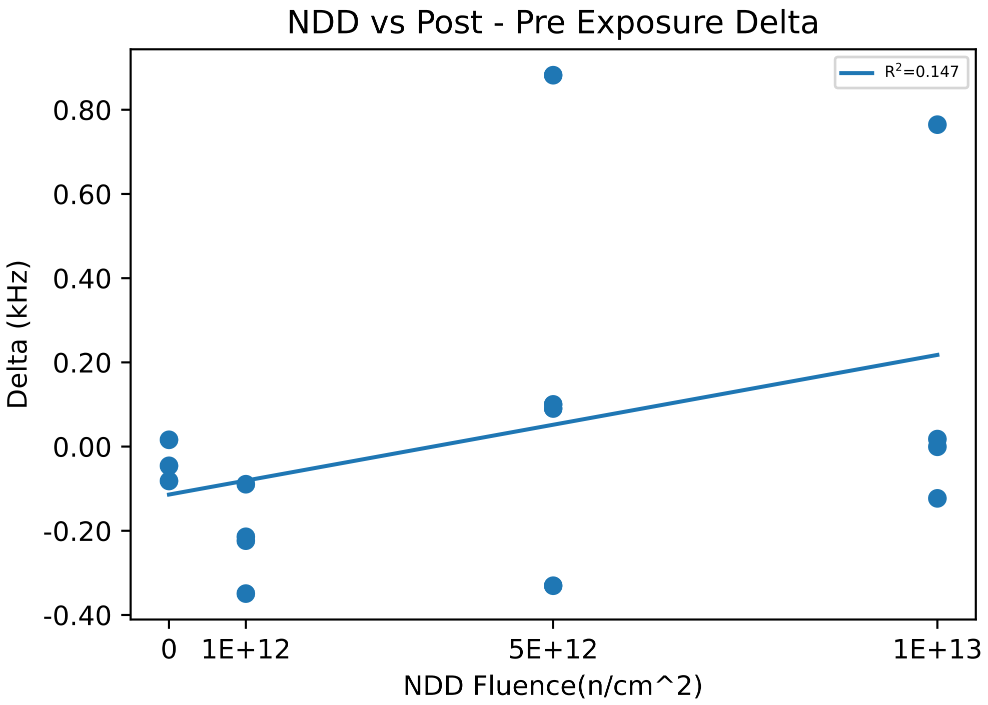
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.275	1.2757	0.0007
2	1e+12	NDD	1.2757	1.2744	-0.0013
3	1e+12	NDD	1.2768	1.2707	-0.0061
4	1e+12	NDD	1.2753	1.2754	0.0001
5	5e+12	NDD	1.2757	1.2744	-0.0013
6	5e+12	NDD	1.2765	1.2707	-0.0058
7	5e+12	NDD	1.2753	1.2757	0.0004
8	5e+12	NDD	1.2757	1.2744	-0.0013
9	1e+13	NDD	1.2768	1.2707	-0.0061
10	1e+13	NDD	1.275	1.2754	0.0004
11	1e+13	NDD	1.276	1.2744	-0.0016
12	1e+13	NDD	1.3161	1.271	-0.0451
13	0	CORRELATION	1.275	1.2757	0.0007
14	0	CORRELATION	1.2757	1.2744	-0.0013
15	0	CORRELATION	1.2765	1.2707	-0.0058

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.275	1.2757	1.2765	0.00075056	1.2707	1.2736	1.2757	0.0025942	-0.0058	-0.0021333	0.0007	0.0033292
1e+12	1.275	1.2757	1.2768	0.0007874	1.2707	1.274	1.2757	0.0023014	-0.0061	-0.00165	0.0007	0.0030827
5e+12	1.2753	1.2758	1.2765	0.00050332	1.2707	1.2738	1.2757	0.0021556	-0.0058	-0.002	0.0004	0.0026571
1e+13	1.275	1.286	1.3161	0.020097	1.2707	1.2729	1.2754	0.0023768	-0.0451	-0.0131	0.0004	0.021506

Device Test: 20.51 LEVEL|FREQ/RT/14/14/0/0/5/500kHz//@FSW_EXT_RT_C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

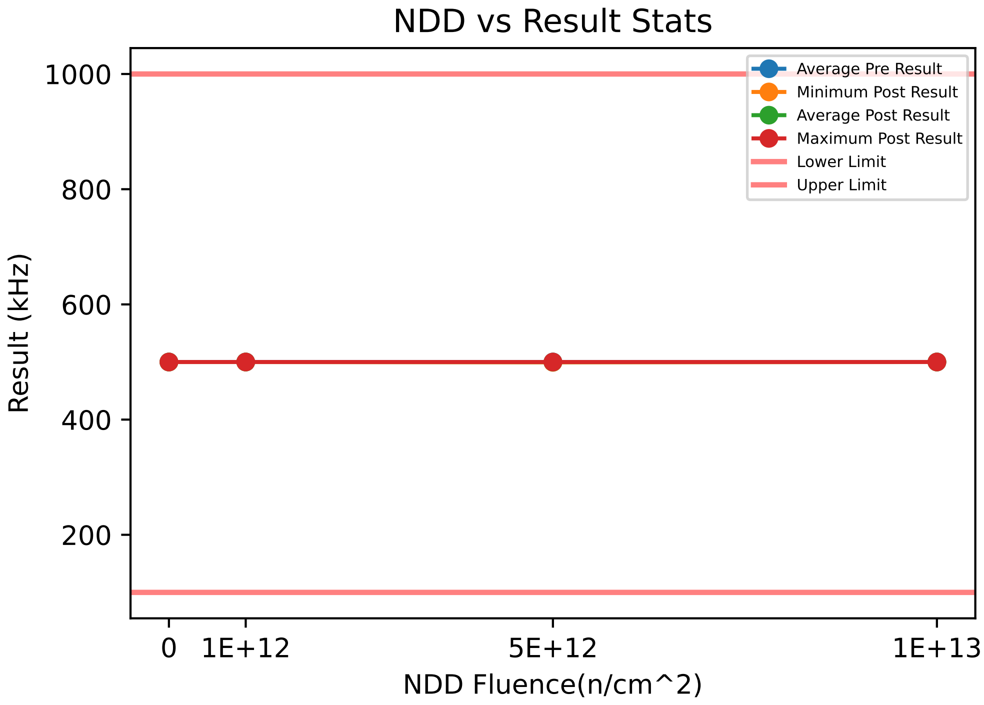
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

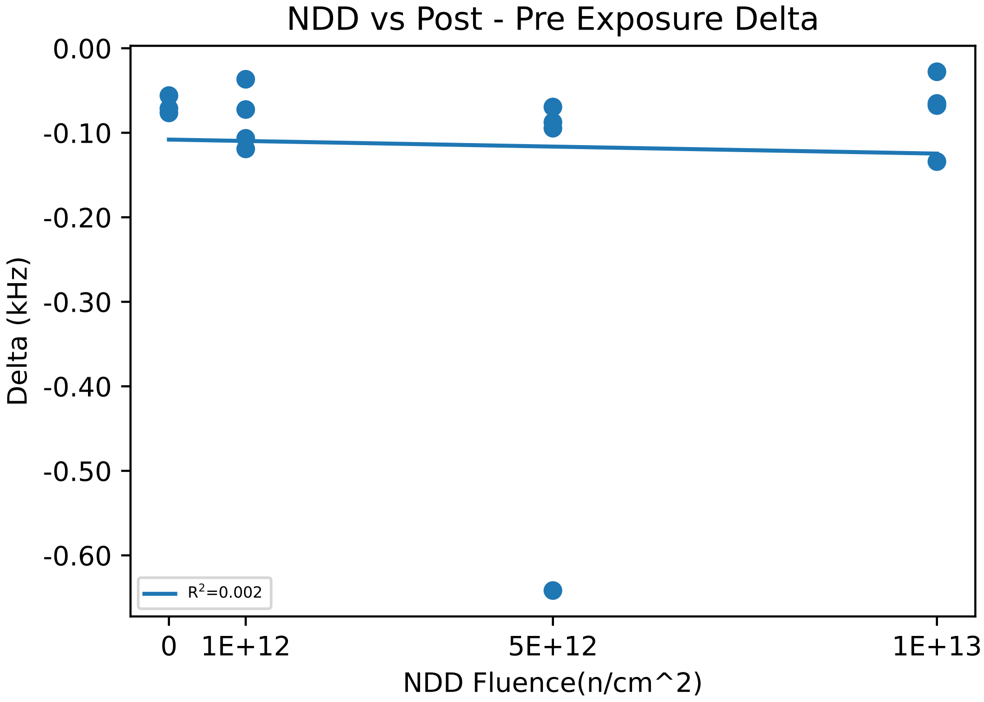
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.66	505.45	-0.2143
2	1e+12	NDD	499.04	498.82	-0.2235
3	1e+12	NDD	499.05	498.96	-0.0894
4	1e+12	NDD	501.21	500.86	-0.3492
5	5e+12	NDD	487.25	487.35	0.1002
6	5e+12	NDD	497.01	497.1	0.0904
7	5e+12	NDD	503.84	504.72	0.8821
8	5e+12	NDD	507.44	507.11	-0.3305
9	1e+13	NDD	505.77	506.54	0.7646
10	1e+13	NDD	505.9	505.9	-0.0005
11	1e+13	NDD	507.31	507.18	-0.123
12	1e+13	NDD	504.04	504.06	0.0178
13	0	CORRELATION	499.24	499.2	-0.0457
14	0	CORRELATION	503.63	503.64	0.0161
15	0	CORRELATION	496.27	496.19	-0.0817

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.27	499.71	503.63	3.7018	496.19	499.67	503.64	3.7512	-0.0817	-0.0371	0.0161	0.049464
1e+12	499.04	501.24	505.66	3.1209	498.82	501.02	505.45	3.096	-0.3492	-0.2191	-0.0894	0.10613
5e+12	487.25	498.88	507.44	8.8791	487.35	499.07	507.11	8.9013	-0.3305	0.18555	0.8821	0.50591
1e+13	504.04	505.75	507.31	1.3371	504.06	505.92	507.18	1.3463	-0.123	0.16473	0.7646	0.40477

Device Test: 20.52 LEVEL|FREQ/SYNC/14/14/0/0/5/500kHz//@FREQ_SYNC_EXT





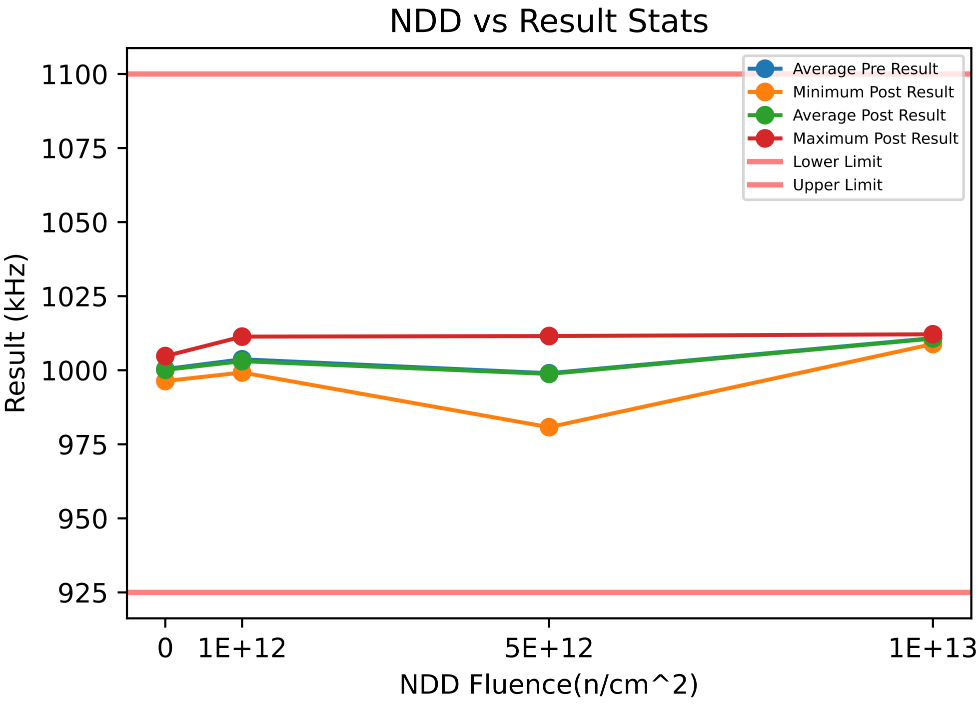
Test Results (Lower Limit = 100.0,
Upper Limit = 1000.0 (kHz))

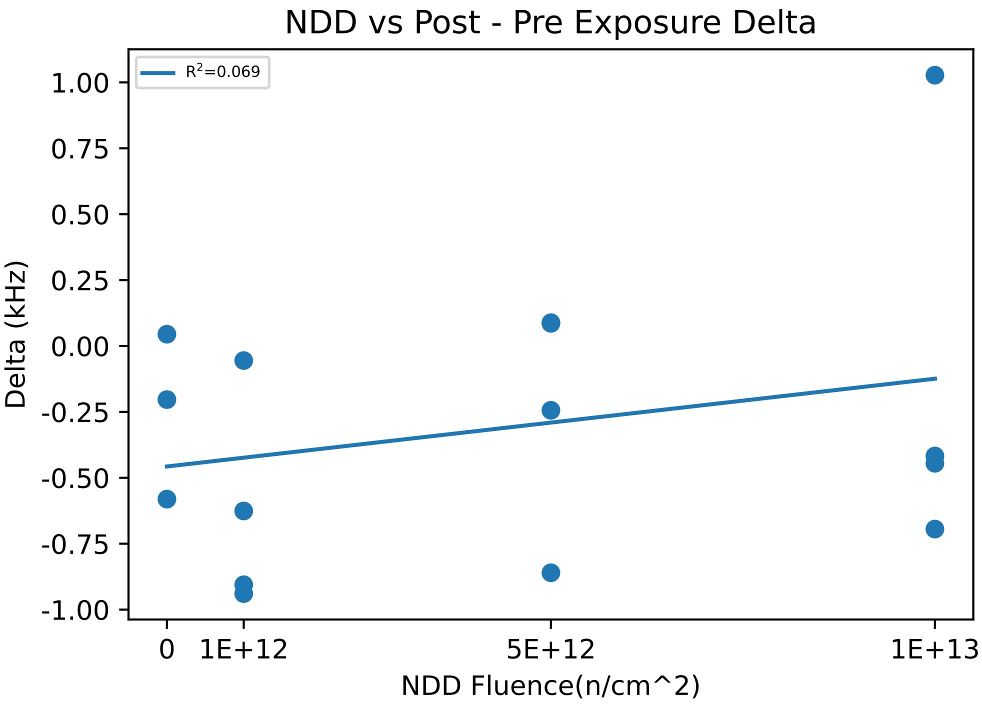
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.01	499.97	-0.0367
2	1e+12	NDD	500.08	500.01	-0.0725
3	1e+12	NDD	500.08	499.97	-0.1066
4	1e+12	NDD	500.05	499.94	-0.1191
5	5e+12	NDD	500.06	499.97	-0.0875
6	5e+12	NDD	500.03	499.39	-0.6416
7	5e+12	NDD	500.04	499.97	-0.0695
8	5e+12	NDD	500.07	499.98	-0.0946
9	1e+13	NDD	500.08	500.01	-0.0678
10	1e+13	NDD	500	499.97	-0.0278
11	1e+13	NDD	500.07	500.01	-0.0653
12	1e+13	NDD	500.11	499.98	-0.1341
13	0	CORRELATION	500.01	499.93	-0.0765
14	0	CORRELATION	500.02	499.97	-0.056
15	0	CORRELATION	500.05	499.98	-0.0713

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.01	500.03	500.05	0.018182	499.93	499.96	499.98	0.021219	-0.0765	-0.067933	-0.056	0.010657
1e+12	500.01	500.06	500.08	0.033501	499.94	499.97	500.01	0.028968	-0.1191	-0.083725	-0.0367	0.037023
5e+12	500.03	500.05	500.07	0.018676	499.39	499.83	499.98	0.29365	-0.6416	-0.2233	-0.0695	0.27907
1e+13	500	500.07	500.11	0.045785	499.97	499.99	500.01	0.020149	-0.1341	-0.07375	-0.0278	0.044198

Device Test: 20.55 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/1MHz//@FSW_EXT_RT_D





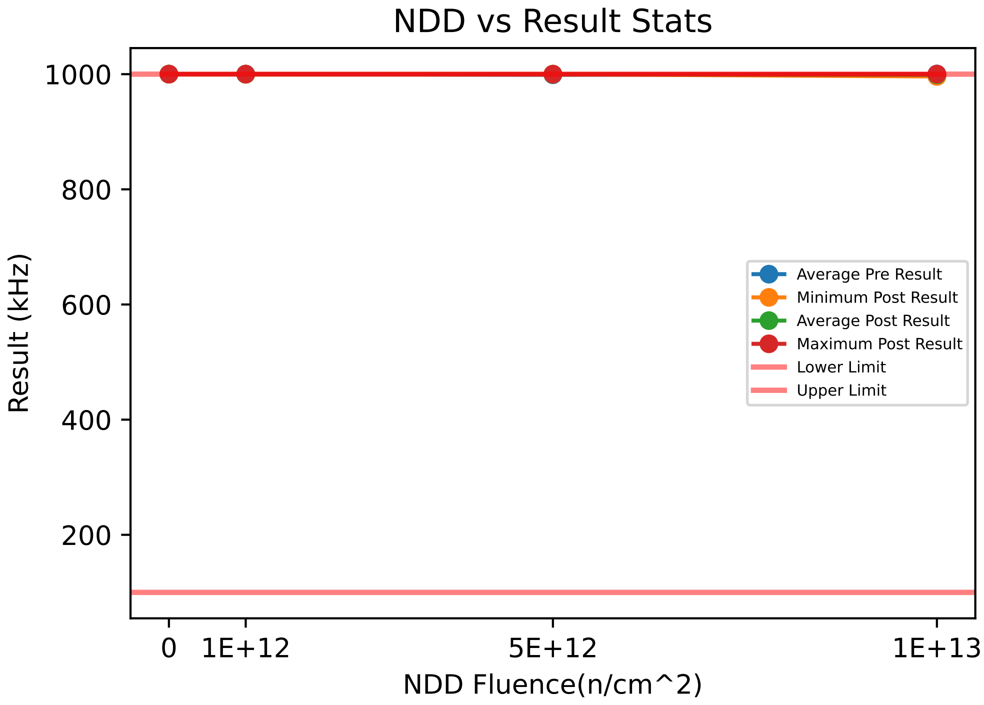
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

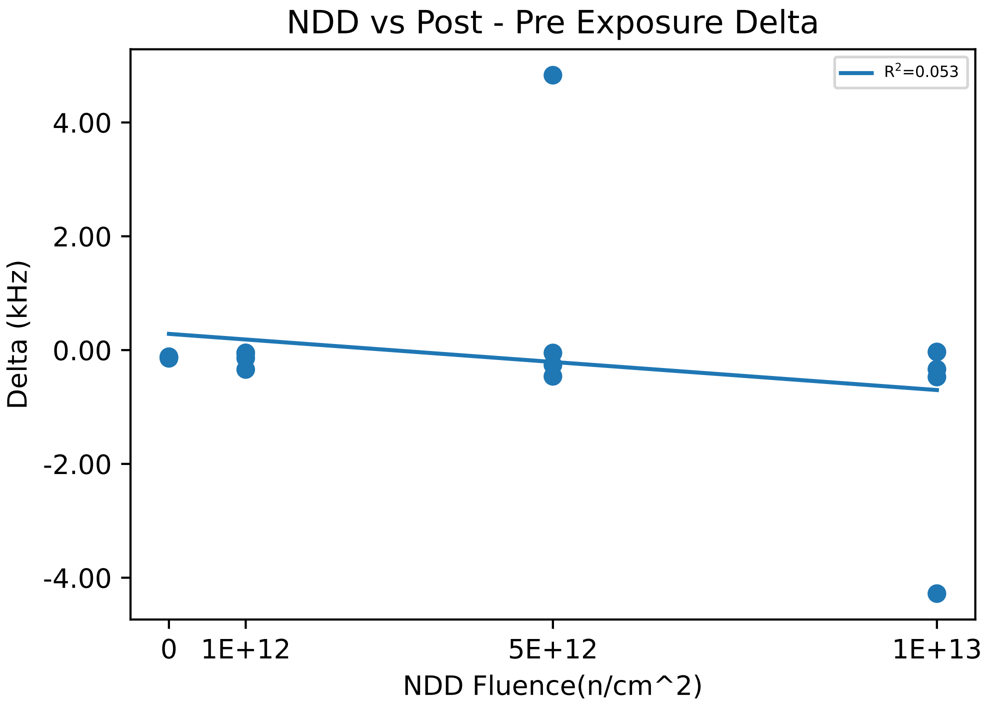
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1012.3	1011.3	-0.9392
2	1e+12	NDD	999.85	999.23	-0.6258
3	1e+12	NDD	999.71	999.65	-0.0552
4	1e+12	NDD	1002.9	1002	-0.9056
5	5e+12	NDD	981.01	980.77	-0.2439
6	5e+12	NDD	998.31	998.4	0.0884
7	5e+12	NDD	1004.2	1004.3	0.0859
8	5e+12	NDD	1012.4	1011.5	-0.8602
9	1e+13	NDD	1011.1	1012.1	1.0272
10	1e+13	NDD	1011.9	1011.2	-0.6945
11	1e+13	NDD	1011	1010.6	-0.4172
12	1e+13	NDD	1009.3	1008.9	-0.4449
13	0	CORRELATION	999.84	999.26	-0.5808
14	0	CORRELATION	1005	1004.8	-0.2033
15	0	CORRELATION	996.3	996.34	0.0447

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	996.3	1000.4	1005	4.3597	996.34	1000.1	1004.8	4.2773	-0.5808	-0.24647	0.0447	0.31498
1e+12	999.71	1003.7	1012.3	5.9153	999.23	1003.1	1011.3	5.6562	-0.9392	-0.63145	-0.0552	0.40905
5e+12	981.01	998.98	1012.4	13.299	980.77	998.75	1011.5	13.136	-0.8602	-0.23245	0.0884	0.44665
1e+13	1009.3	1010.8	1011.9	1.1001	1008.9	1010.7	1012.1	1.3866	-0.6945	-0.13235	1.0272	0.78303

Device Test: 20.56 LEVEL|FREQ/SYNC/4.5/4.5/0/0/4.5/1MHz//@FREQ_SYNC_EXT





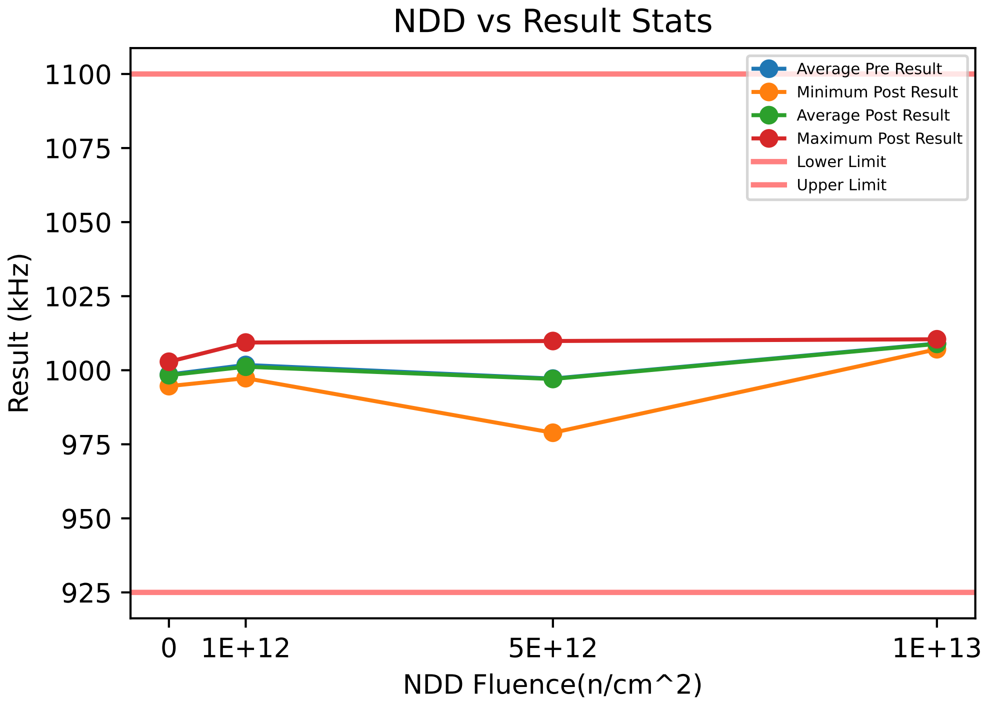
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

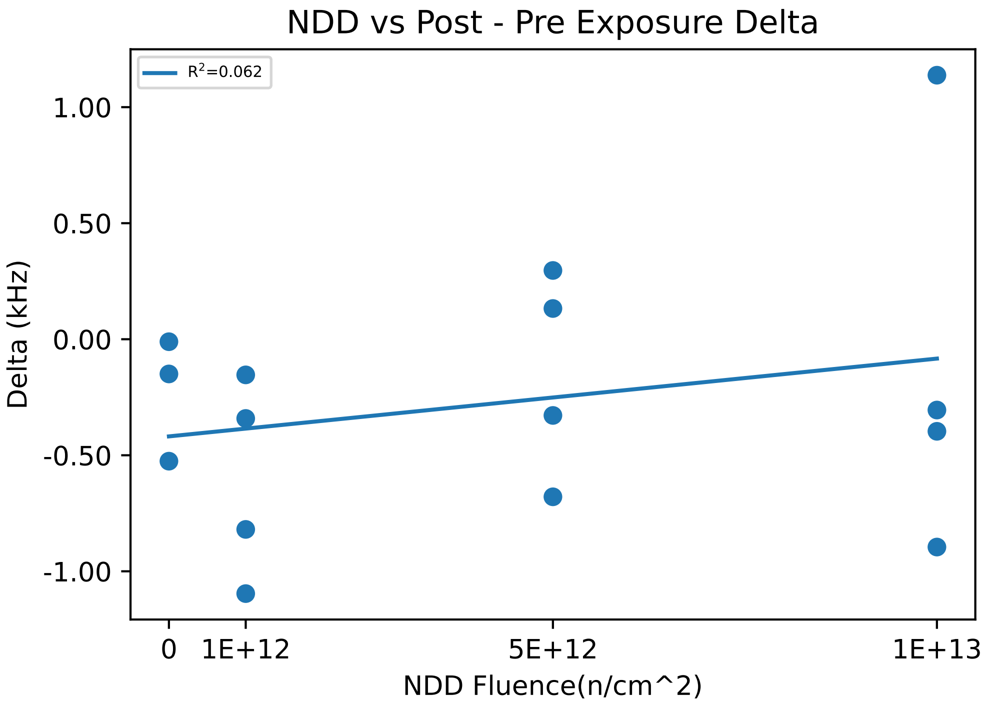
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000	999.9	-0.1417
2	1e+12	NDD	1000.1	1000.1	-0.0583
3	1e+12	NDD	1000.2	1000.1	-0.0483
4	1e+12	NDD	1000.1	999.71	-0.341
5	5e+12	NDD	1000.2	999.89	-0.2612
6	5e+12	NDD	1000.4	999.91	-0.4612
7	5e+12	NDD	995.1	999.93	4.8306
8	5e+12	NDD	1000.1	1000	-0.0502
9	1e+13	NDD	1000.5	1000.1	-0.3364
10	1e+13	NDD	1000.2	999.73	-0.4729
11	1e+13	NDD	1000.3	996	-4.279
12	1e+13	NDD	1000.2	1000.2	-0.0326
13	0	CORRELATION	1000	999.9	-0.1447
14	0	CORRELATION	1000.2	1000	-0.1163
15	0	CORRELATION	1000.2	1000.1	-0.1288

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000	1000.1	1000.2	0.097097	999.9	1000	1000.1	0.10676	-0.1447	-0.12993	-0.1163	0.014234
1e+12	1000	1000.1	1000.2	0.05988	999.71	999.95	1000.1	0.18285	-0.341	-0.14733	-0.0483	0.13574
5e+12	995.1	998.93	1000.4	2.5589	999.89	999.94	1000	0.068061	-0.4612	1.0145	4.8306	2.5496
1e+13	1000.2	1000.3	1000.5	0.12848	996	999	1000.2	2.0119	-4.279	-1.2802	-0.0326	2.0076

Device Test: 20.59 LEVEL|FREQ/RT/5/5/0/0/5/1MHz//@FSW_EXT_RT_D





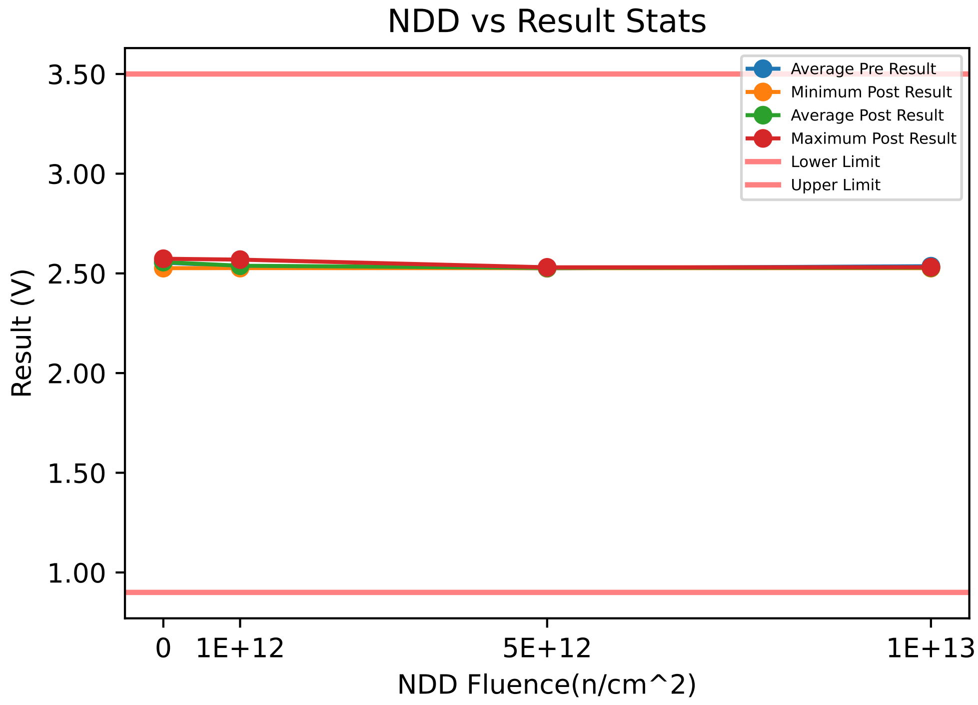
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

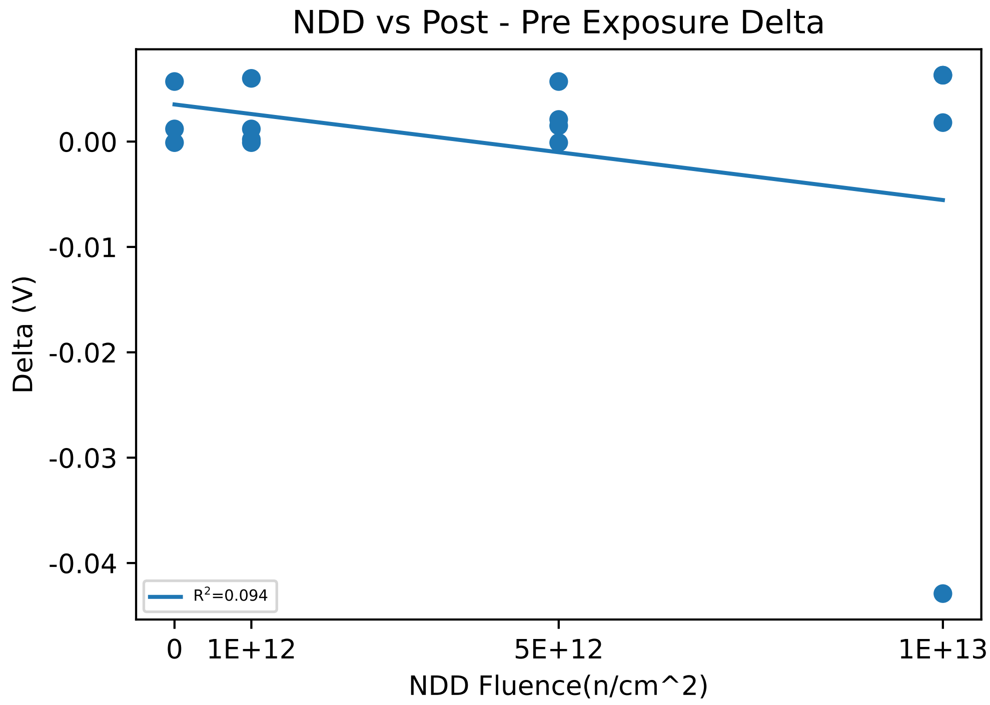
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1010.4	1009.4	-1.0961
2	1e+12	NDD	997.67	997.32	-0.3414
3	1e+12	NDD	998.12	997.96	-0.1536
4	1e+12	NDD	1000.9	1000.1	-0.8195
5	5e+12	NDD	979.22	978.89	-0.3284
6	5e+12	NDD	996.45	996.58	0.1324
7	5e+12	NDD	1002.5	1002.8	0.2963
8	5e+12	NDD	1010.5	1009.9	-0.679
9	1e+13	NDD	1009.3	1010.5	1.1377
10	1e+13	NDD	1010.1	1009.2	-0.8955
11	1e+13	NDD	1009.1	1008.8	-0.3051
12	1e+13	NDD	1007.5	1007.1	-0.3968
13	0	CORRELATION	998	997.48	-0.5255
14	0	CORRELATION	1003	1002.9	-0.1496
15	0	CORRELATION	994.64	994.63	-0.0107

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.64	998.55	1003	4.213	994.63	998.32	1002.9	4.1812	-0.5255	-0.2286	-0.0107	0.26634
1e+12	997.67	1001.8	1010.4	5.9509	997.32	1001.2	1009.4	5.5734	-1.0961	-0.60265	-0.1536	0.43221
5e+12	979.22	997.18	1010.5	13.291	978.89	997.04	1009.9	13.256	-0.679	-0.14468	0.2963	0.44365
1e+13	1007.5	1009	1010.1	1.1114	1007.1	1008.9	1010.5	1.3958	-0.8955	-0.11492	1.1377	0.87445

Device Test: 20.6 LEVEL|HIGH_LEVEL/SYNC/5/5/0/0/4.5/500kHz//@SYNC_VIH_TH_HIGH_4P5





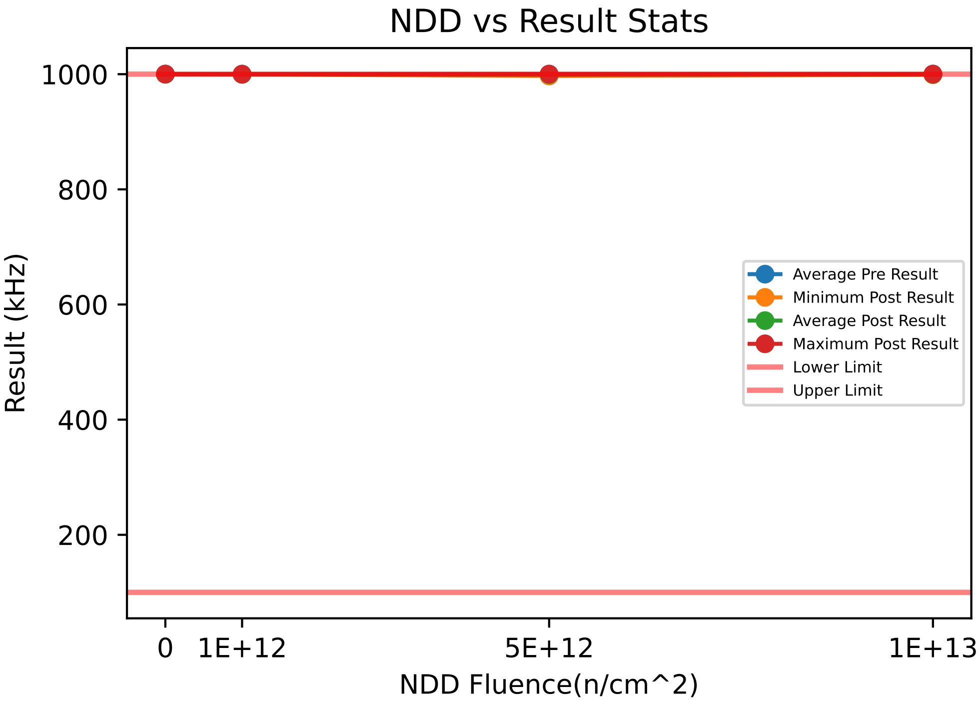
Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

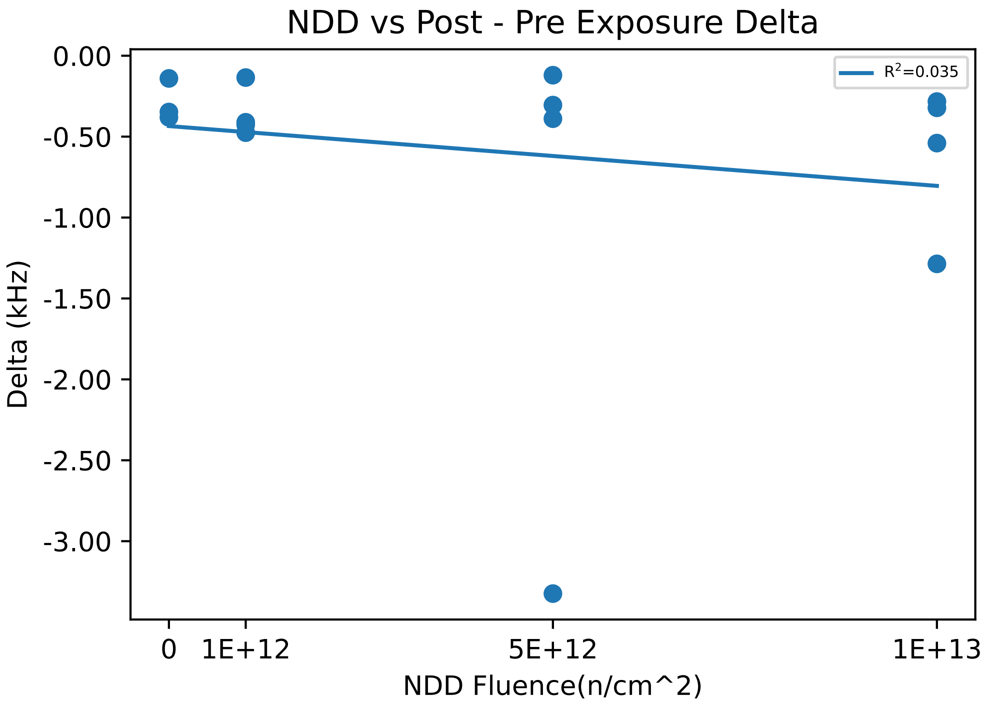
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.5691	2.569	-0.0001
2	1e+12	NDD	2.5257	2.5269	0.0012
3	1e+12	NDD	2.5247	2.5307	0.006
4	1e+12	NDD	2.5263	2.5265	0.0002
5	5e+12	NDD	2.5257	2.5272	0.0015
6	5e+12	NDD	2.5247	2.5304	0.0057
7	5e+12	NDD	2.5263	2.5262	-0.0001
8	5e+12	NDD	2.5257	2.5278	0.0021
9	1e+13	NDD	2.5247	2.531	0.0063
10	1e+13	NDD	2.5691	2.5262	-0.0429
11	1e+13	NDD	2.5257	2.5275	0.0018
12	1e+13	NDD	2.5247	2.531	0.0063
13	0	CORRELATION	2.5263	2.5262	-0.0001
14	0	CORRELATION	2.5688	2.57	0.0012
15	0	CORRELATION	2.5678	2.5735	0.0057

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5263	2.5543	2.5688	0.024254	2.5262	2.5566	2.5735	0.026356	-0.0001	0.0022667	0.0057	0.0030436
1e+12	2.5247	2.5365	2.5691	0.021777	2.5265	2.5383	2.569	0.020571	-0.0001	0.001825	0.006	0.0028383
5e+12	2.5247	2.5256	2.5263	0.00066332	2.5262	2.5279	2.5304	0.0017926	-0.0001	0.0023	0.0057	0.0024495
1e+13	2.5247	2.5361	2.5691	0.022038	2.5262	2.5289	2.531	0.0024541	-0.0429	-0.007125	0.0063	0.023944

Device Test: 20.60 LEVEL|FREQ/SYNC/5/5/0/0/5/1MHz//@FREQ_SYNC_EXT





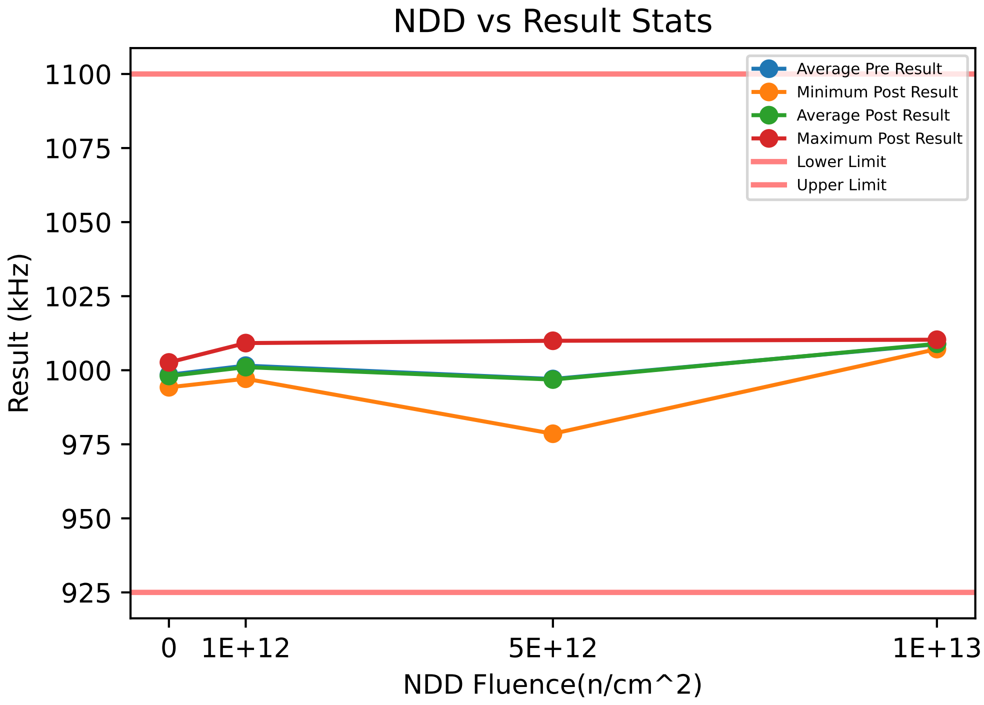
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

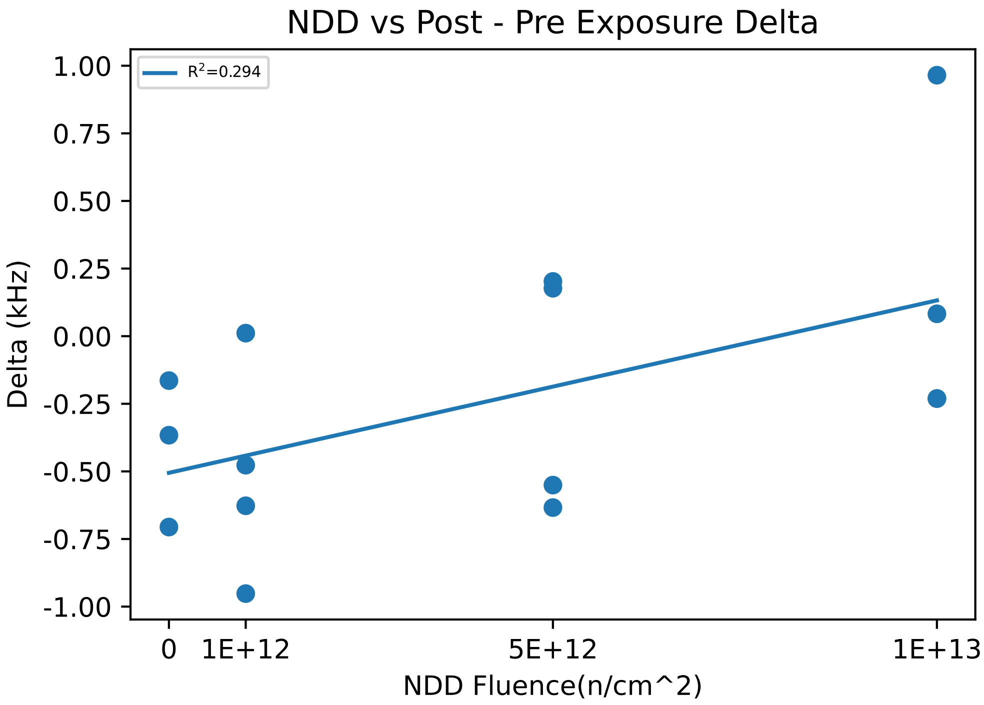
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000	999.88	-0.1349
2	1e+12	NDD	1000.3	999.86	-0.4112
3	1e+12	NDD	1000.4	999.93	-0.4264
4	1e+12	NDD	1000.2	999.7	-0.4753
5	5e+12	NDD	1000.1	996.79	-3.3239
6	5e+12	NDD	1000.2	1000.1	-0.1203
7	5e+12	NDD	1000.2	999.87	-0.305
8	5e+12	NDD	1000.3	999.86	-0.3891
9	1e+13	NDD	1000.5	999.93	-0.5399
10	1e+13	NDD	1000.2	998.94	-1.2862
11	1e+13	NDD	1000.1	999.86	-0.2831
12	1e+13	NDD	1000.4	1000.1	-0.3218
13	0	CORRELATION	1000.1	999.95	-0.1402
14	0	CORRELATION	1000.2	999.85	-0.3479
15	0	CORRELATION	1000.5	1000.1	-0.381

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000.1	1000.3	1000.5	0.19994	999.85	999.96	1000.1	0.12461	-0.381	-0.2897	-0.1402	0.13052
1e+12	1000	1000.2	1000.4	0.14756	999.7	999.84	999.93	0.097485	-0.4753	-0.36195	-0.1349	0.15382
5e+12	1000.1	1000.2	1000.3	0.054574	996.79	999.15	1000.1	1.5728	-3.3239	-1.0346	-0.1203	1.5303
1e+13	1000.1	1000.3	1000.5	0.14987	998.94	999.7	1000.1	0.51502	-1.2862	-0.60775	-0.2831	0.46621

Device Test: 20.63 LEVEL|FREQ/RT/12/12/0/0/5/1MHz//@FSW_EXT_RT_D





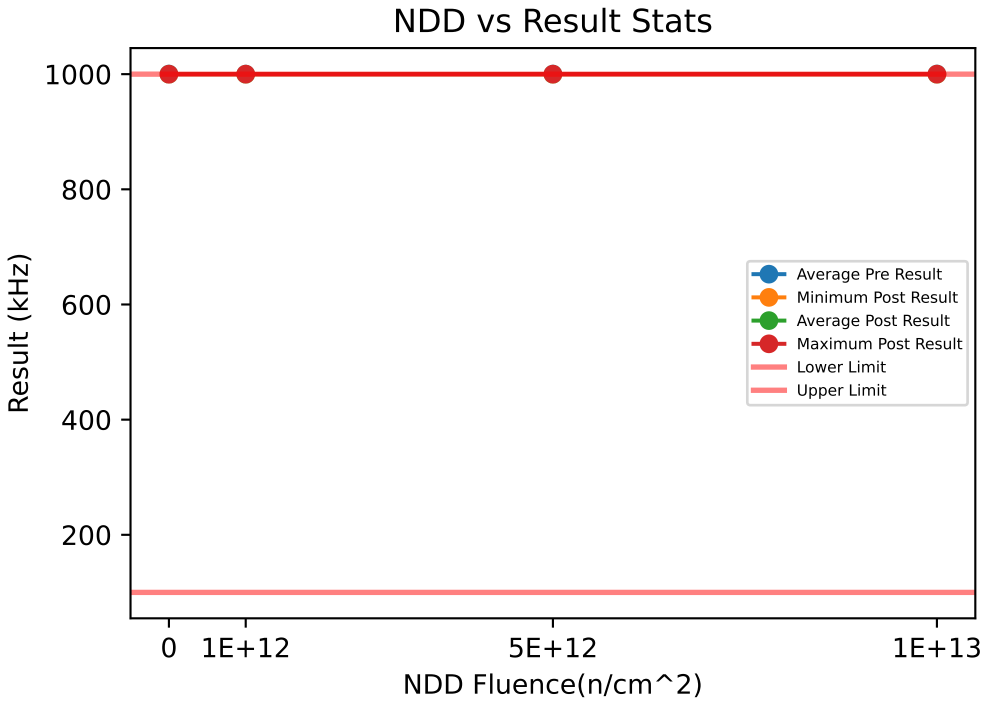
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1010.1	1009.2	-0.9519
2	1e+12	NDD	997.6	997.13	-0.477
3	1e+12	NDD	997.79	997.8	0.0112
4	1e+12	NDD	1000.7	1000.1	-0.6271
5	5e+12	NDD	979.11	978.55	-0.5507
6	5e+12	NDD	996.07	996.28	0.2024
7	5e+12	NDD	1002.4	1002.6	0.1772
8	5e+12	NDD	1010.6	1009.9	-0.6338
9	1e+13	NDD	1009.3	1010.3	0.965
10	1e+13	NDD	1009.7	1009.4	-0.2308
11	1e+13	NDD	1009	1008.8	-0.2305
12	1e+13	NDD	1007.1	1007.1	0.0827
13	0	CORRELATION	998	997.29	-0.7058
14	0	CORRELATION	1002.8	1002.6	-0.1643
15	0	CORRELATION	994.6	994.23	-0.3662

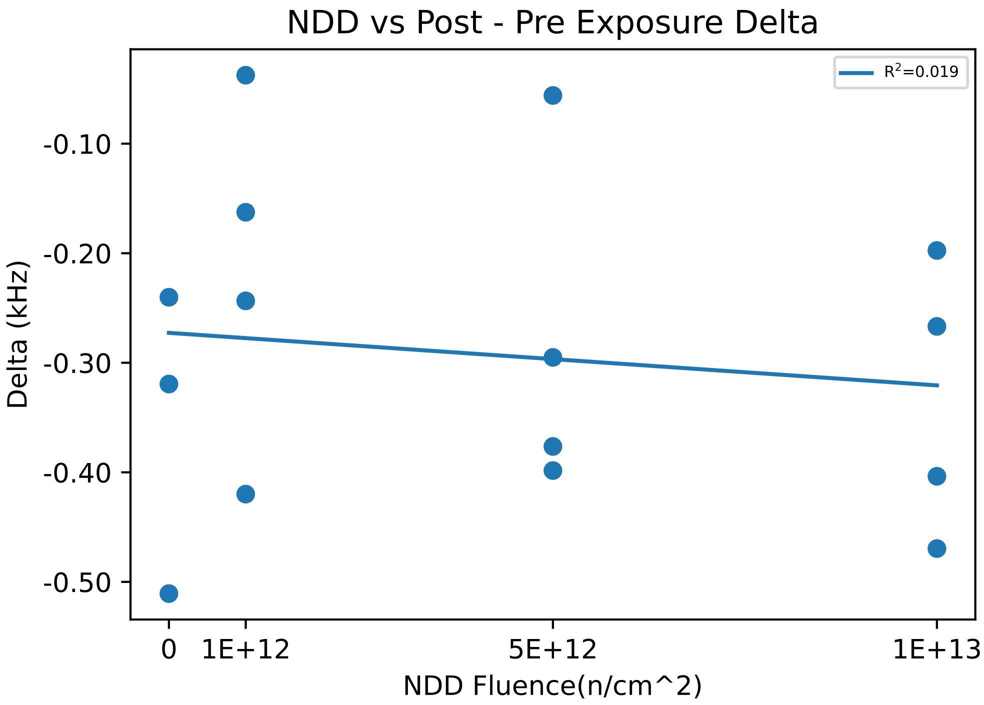
Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.6	998.47	1002.8	4.1206	994.23	998.05	1002.6	4.2529	-0.7058	-0.4121	-0.1643	0.27365
1e+12	997.6	1001.6	1010.1	5.8835	997.13	1001	1009.2	5.5611	-0.9519	-0.5112	0.0112	0.40072
5e+12	979.11	997.04	1010.6	13.351	978.55	996.84	1009.9	13.41	-0.6338	-0.20123	0.2024	0.45291
1e+13	1007.1	1008.8	1009.7	1.1691	1007.1	1008.9	1010.3	1.3337	-0.2308	0.1466	0.965	0.56524

Device Test: 20.64 LEVEL|FREQ/SYNC/12/12/0/0/5/1MHz//@FREQ_SYNC_EXT



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

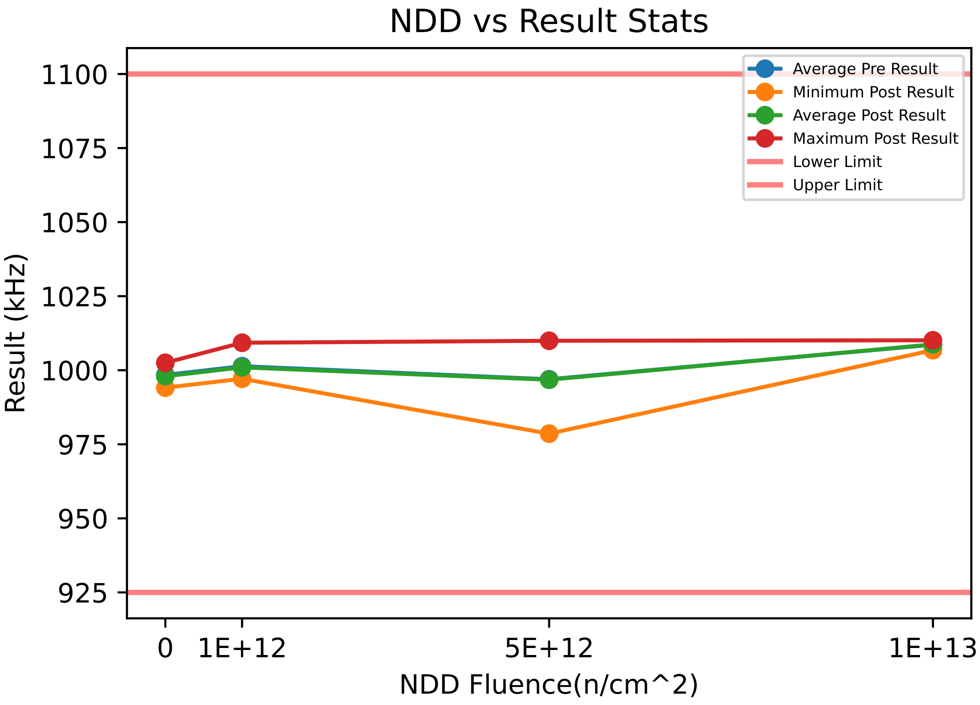
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

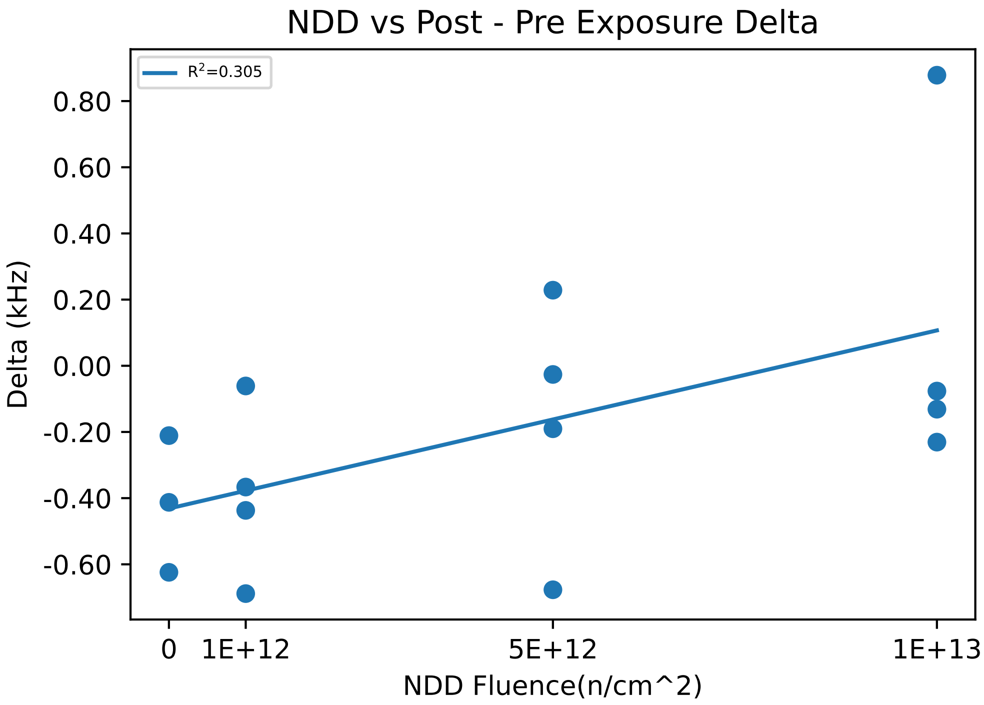
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000	999.76	-0.2435
2	1e+12	NDD	1000.1	1000.1	-0.0375
3	1e+12	NDD	1000.1	999.96	-0.1626
4	1e+12	NDD	1000.2	999.74	-0.4199
5	5e+12	NDD	1000.1	1000	-0.056
6	5e+12	NDD	1000.3	999.92	-0.3764
7	5e+12	NDD	1000.1	999.72	-0.3984
8	5e+12	NDD	1000.2	999.89	-0.2951
9	1e+13	NDD	1000.3	1000.1	-0.2668
10	1e+13	NDD	1000.2	999.74	-0.4696
11	1e+13	NDD	1000.3	999.9	-0.4036
12	1e+13	NDD	1000.2	1000	-0.1975
13	0	CORRELATION	1000.1	999.87	-0.2402
14	0	CORRELATION	1000.2	999.83	-0.3194
15	0	CORRELATION	1000.4	999.93	-0.5107

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000.1	1000.2	1000.4	0.1816	999.83	999.88	999.93	0.05021	-0.5107	-0.35677	-0.2402	0.13907
1e+12	1000	1000.1	1000.2	0.06942	999.74	999.88	1000.1	0.15451	-0.4199	-0.21588	-0.0375	0.16026
5e+12	1000.1	1000.2	1000.3	0.092178	999.72	999.89	1000	0.13211	-0.3984	-0.28147	-0.056	0.15674
1e+13	1000.2	1000.3	1000.3	0.057002	999.74	999.93	1000.1	0.14388	-0.4696	-0.33437	-0.1975	0.12434

Device Test: 20.67 LEVEL|FREQ/RT/14/14/0/0/5/1MHz//@FSW_EXT_RT_D





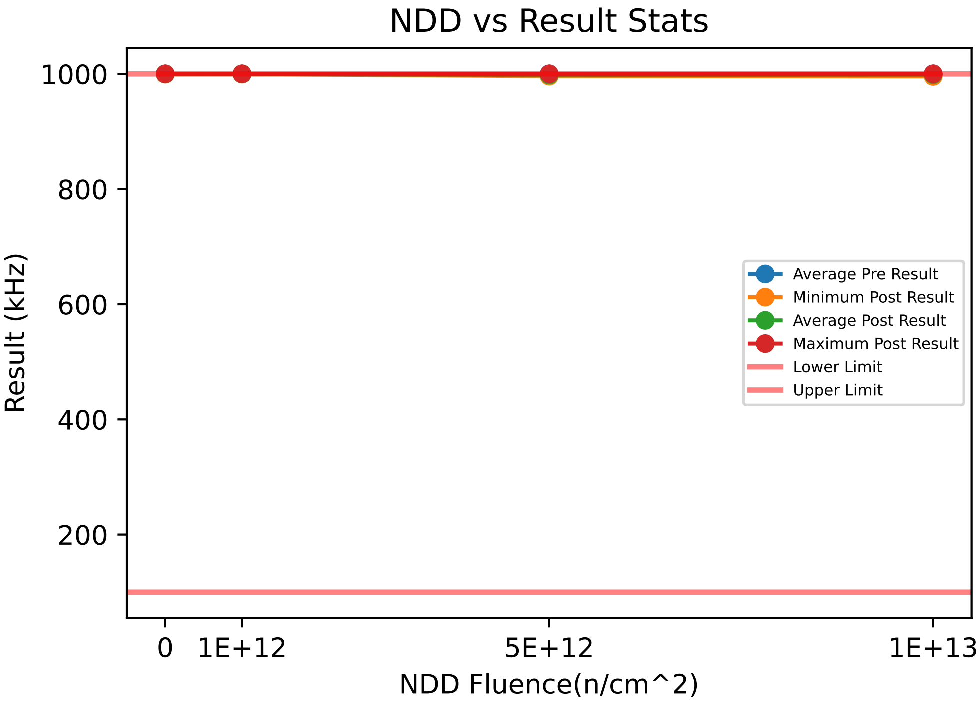
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

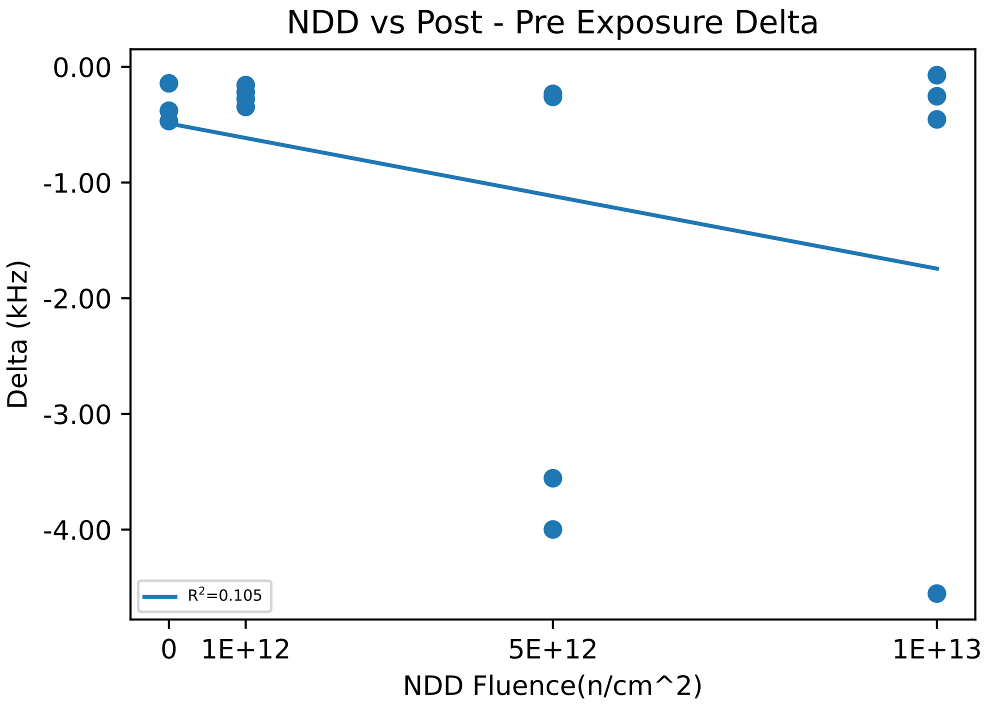
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1009.7	1009.3	-0.437
2	1e+12	NDD	997.49	997.12	-0.3665
3	1e+12	NDD	997.57	997.51	-0.061
4	1e+12	NDD	1000.7	999.97	-0.6885
5	5e+12	NDD	978.77	978.58	-0.1903
6	5e+12	NDD	996.03	996.01	-0.0262
7	5e+12	NDD	1002.4	1002.6	0.2285
8	5e+12	NDD	1010.6	1009.9	-0.6769
9	1e+13	NDD	1009.2	1010.1	0.8782
10	1e+13	NDD	1009.5	1009.4	-0.1312
11	1e+13	NDD	1008.9	1008.7	-0.2307
12	1e+13	NDD	1006.8	1006.8	-0.0764
13	0	CORRELATION	997.93	997.3	-0.6242
14	0	CORRELATION	1002.7	1002.5	-0.211
15	0	CORRELATION	994.52	994.11	-0.4127

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.52	998.39	1002.7	4.1191	994.11	997.98	1002.5	4.2405	-0.6242	-0.41597	-0.211	0.20662
1e+12	997.49	1001.4	1009.7	5.7659	997.12	1001	1009.3	5.6832	-0.6885	-0.38825	-0.061	0.25826
5e+12	978.77	996.95	1010.6	13.509	978.58	996.78	1009.9	13.402	-0.6769	-0.16623	0.2285	0.38157
1e+13	1006.8	1008.6	1009.5	1.2073	1006.8	1008.7	1010.1	1.4332	-0.2307	0.10997	0.8782	0.51612

Device Test: 20.68 LEVEL|FREQ/SYNC/14/14/0/0/5/1MHz//@FREQ_SYNC_EXT





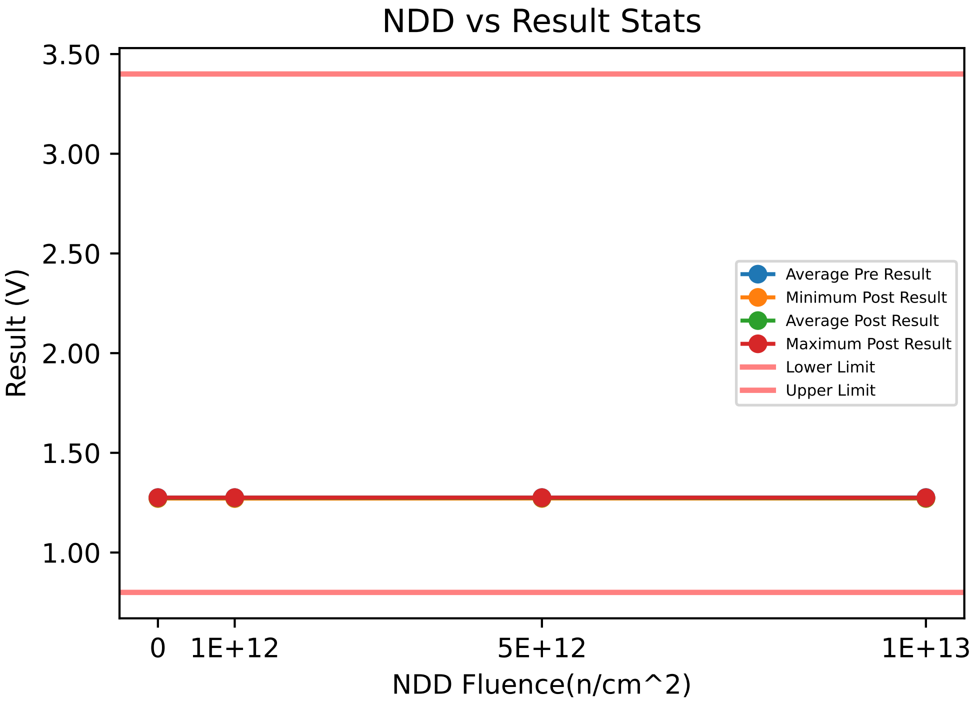
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

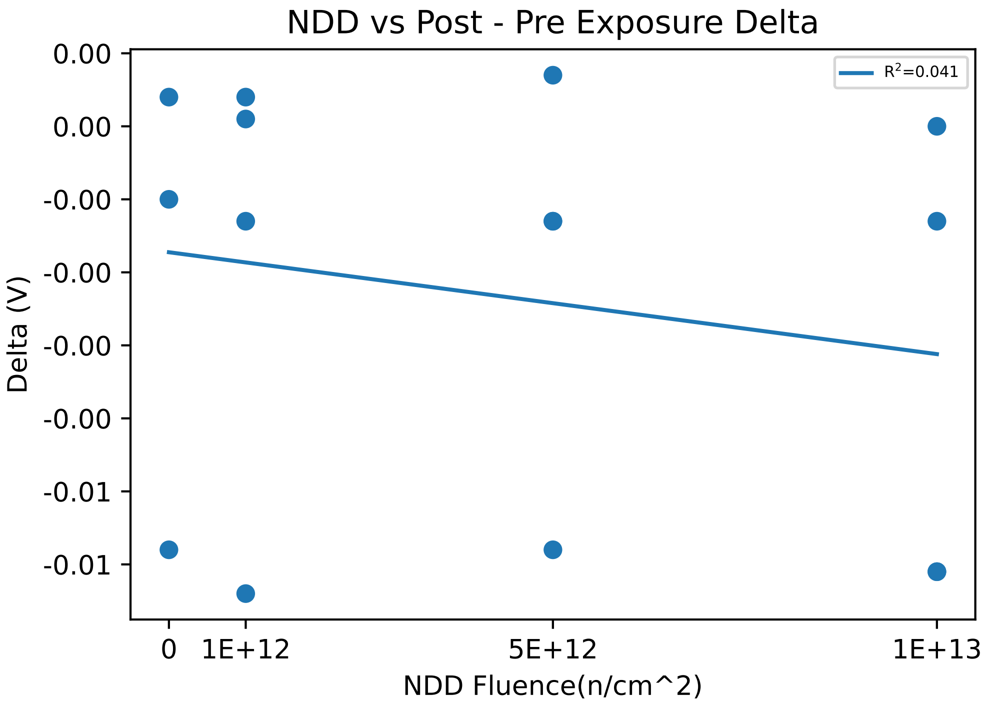
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000.1	999.88	-0.221
2	1e+12	NDD	1000.1	999.86	-0.2772
3	1e+12	NDD	1000.2	1000.1	-0.1576
4	1e+12	NDD	1000.3	999.92	-0.3467
5	5e+12	NDD	1000.3	1000	-0.2597
6	5e+12	NDD	1000.3	1000.1	-0.2336
7	5e+12	NDD	1000.2	996.19	-3.999
8	5e+12	NDD	1000.3	996.73	-3.5561
9	1e+13	NDD	1000.3	995.74	-4.5532
10	1e+13	NDD	1000.2	999.74	-0.4544
11	1e+13	NDD	1000.1	1000.1	-0.0722
12	1e+13	NDD	1000.4	1000.1	-0.2542
13	0	CORRELATION	1000.2	999.72	-0.4687
14	0	CORRELATION	1000.2	1000	-0.1425
15	0	CORRELATION	1000.3	999.93	-0.3797

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000.2	1000.2	1000.3	0.08217	999.72	999.89	1000	0.15204	-0.4687	-0.3303	-0.1425	0.16862
1e+12	1000.1	1000.2	1000.3	0.076975	999.86	999.94	1000.1	0.098928	-0.3467	-0.25063	-0.1576	0.080556
5e+12	1000.2	1000.3	1000.3	0.04969	996.19	998.25	1000.1	2.0785	-3.999	-2.0121	-0.2336	2.0466
1e+13	1000.1	1000.2	1000.4	0.10022	995.74	998.91	1000.1	2.1177	-4.5532	-1.3335	-0.0722	2.1521

Device Test: 20.7 LEVEL|LOW_LEVEL/SYNC/5.5/5.5/0/0/4.5/500kHz//@SYNC_VIL_TH_HIGH_4P5





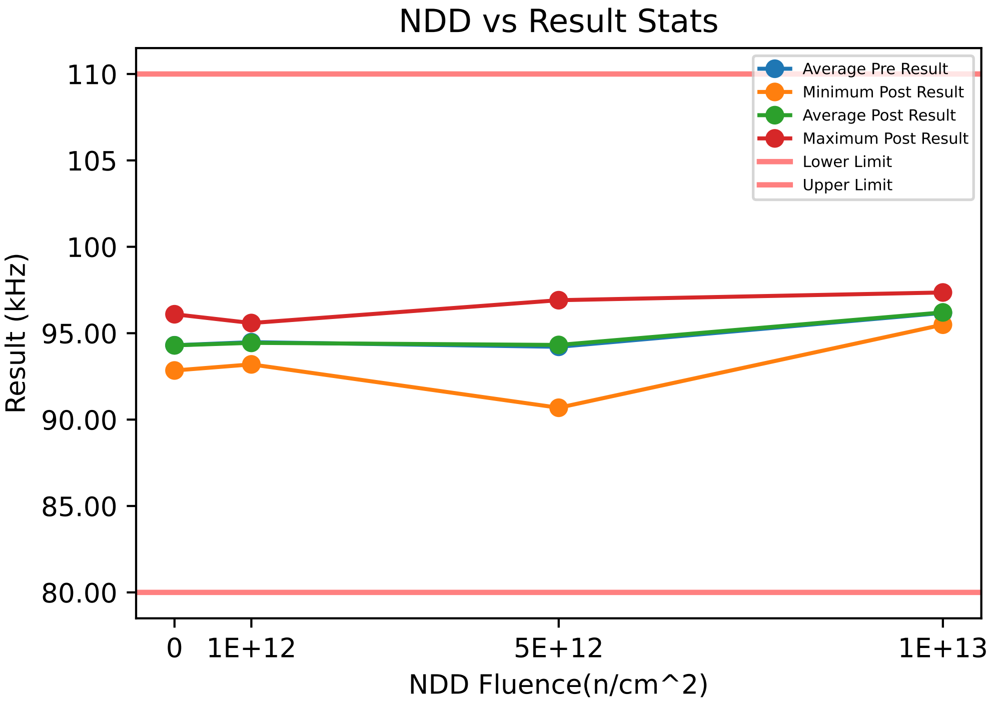
Test Results (Lower Limit = 0.8, Upper Limit = 3.4 (V))

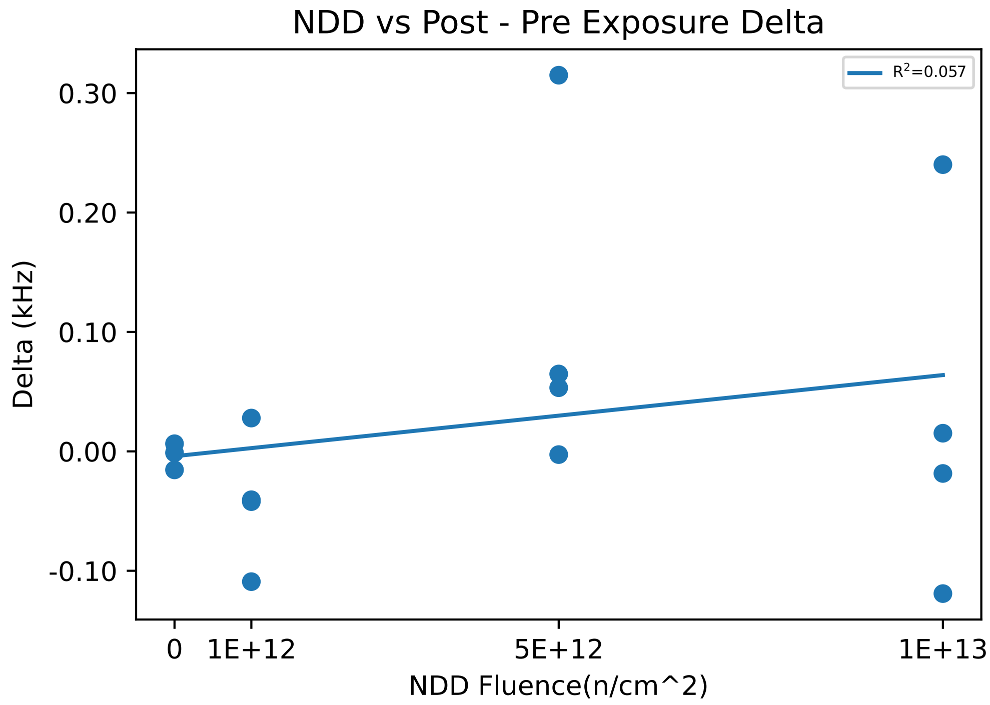
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2753	1.2754	0.0001
2	1e+12	NDD	1.2757	1.2744	-0.0013
3	1e+12	NDD	1.2768	1.2704	-0.0064
4	1e+12	NDD	1.275	1.2754	0.0004
5	5e+12	NDD	1.2757	1.2744	-0.0013
6	5e+12	NDD	1.2768	1.271	-0.0058
7	5e+12	NDD	1.2747	1.2754	0.0007
8	5e+12	NDD	1.2757	1.2744	-0.0013
9	1e+13	NDD	1.2768	1.2707	-0.0061
10	1e+13	NDD	1.275	1.275	0
11	1e+13	NDD	1.2757	1.2744	-0.0013
12	1e+13	NDD	1.2768	1.2707	-0.0061
13	0	CORRELATION	1.275	1.2754	0.0004
14	0	CORRELATION	1.2757	1.2747	-0.001
15	0	CORRELATION	1.2765	1.2707	-0.0058

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.275	1.2757	1.2765	0.00075056	1.2707	1.2736	1.2754	0.0025357	-0.0058	-0.0021333	0.0004	0.0032517
1e+12	1.275	1.2757	1.2768	0.0007874	1.2704	1.2739	1.2754	0.0023805	-0.0064	-0.0018	0.0004	0.0031549
5e+12	1.2747	1.2757	1.2768	0.00085781	1.271	1.2738	1.2754	0.0019253	-0.0058	-0.001925	0.0007	0.00275
1e+13	1.275	1.2761	1.2768	0.00088459	1.2707	1.2727	1.275	0.0023224	-0.0061	-0.003375	0	0.003191

Device Test: 20.71 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/100kHz//@FSW_EXT_RT_A





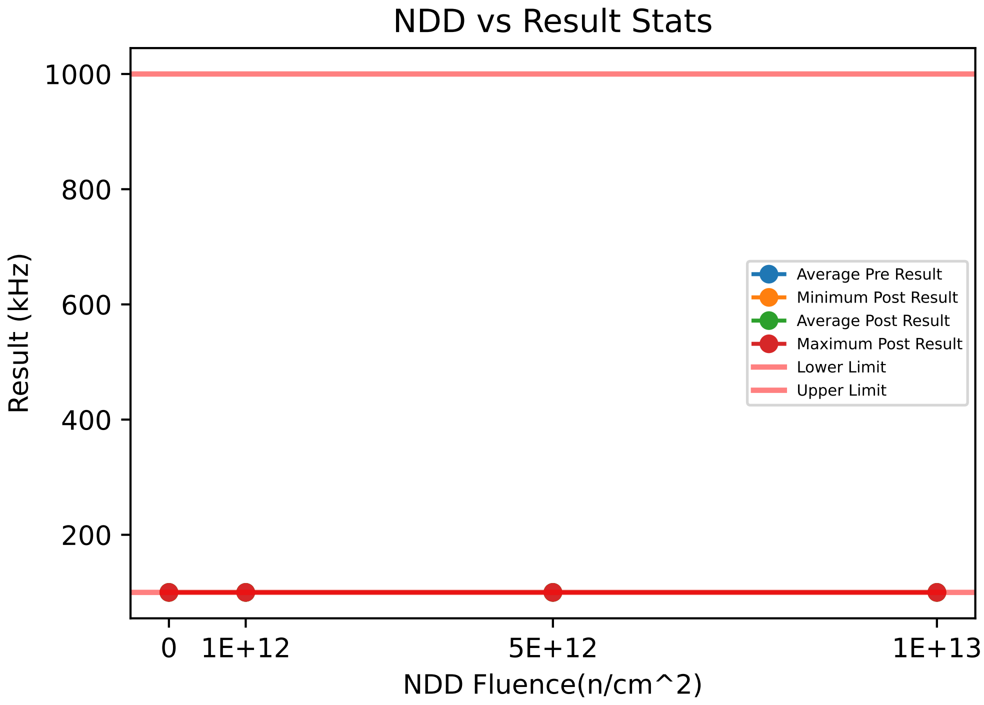
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

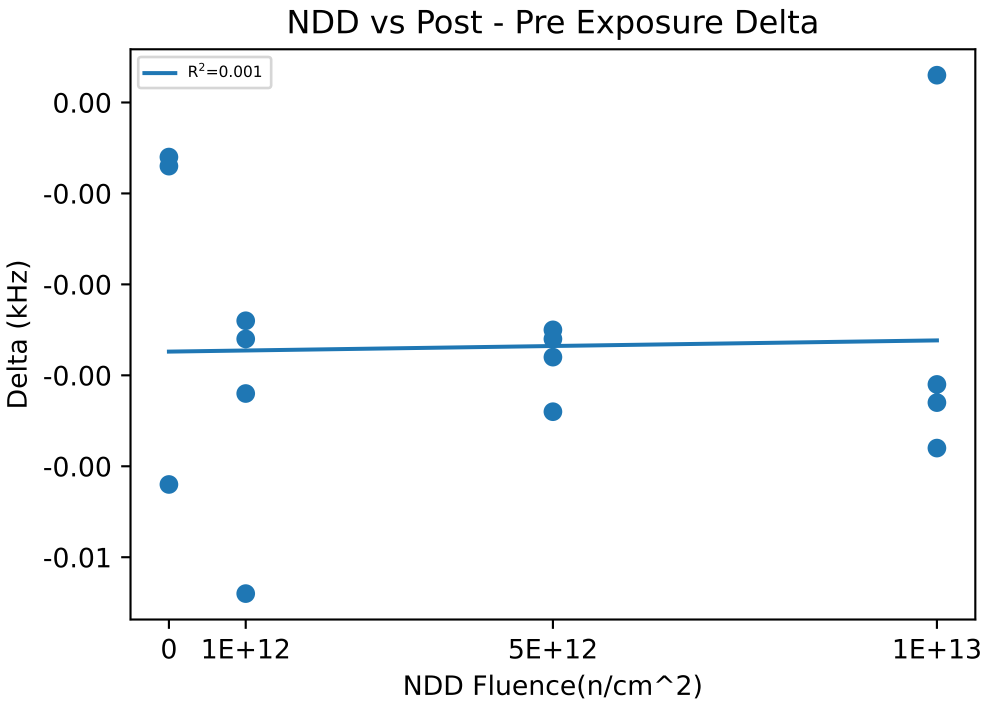
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.631	95.589	-0.0421
2	1e+12	NDD	93.235	93.195	-0.0405
3	1e+12	NDD	94.178	94.206	0.0279
4	1e+12	NDD	94.883	94.774	-0.1091
5	5e+12	NDD	90.621	90.685	0.0648
6	5e+12	NDD	93.008	93.061	0.0533
7	5e+12	NDD	96.31	96.625	0.315
8	5e+12	NDD	96.912	96.91	-0.0027
9	1e+13	NDD	95.64	95.88	0.2401
10	1e+13	NDD	96.071	96.086	0.0152
11	1e+13	NDD	97.476	97.357	-0.1191
12	1e+13	NDD	95.51	95.492	-0.0185
13	0	CORRELATION	93.955	93.954	-0.0012
14	0	CORRELATION	96.09	96.097	0.0064
15	0	CORRELATION	92.858	92.843	-0.0155

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.858	94.301	96.09	1.6435	92.843	94.298	96.097	1.654	-0.0155	-0.0034333	0.0064	0.01112
1e+12	93.235	94.482	95.631	1.021	93.195	94.441	95.589	1.006	-0.1091	-0.04095	0.0279	0.055935
5e+12	90.621	94.213	96.912	2.9462	90.685	94.32	96.91	2.9896	-0.0027	0.1076	0.315	0.14138
1e+13	95.51	96.174	97.476	0.90005	95.492	96.204	97.357	0.80708	-0.1191	0.029425	0.2401	0.15159

Device Test: 20.72 LEVEL|FREQ/SYNC/4.5/4.5/0/1000/4.5/100kHz//@FREQ_SYNC_EXT





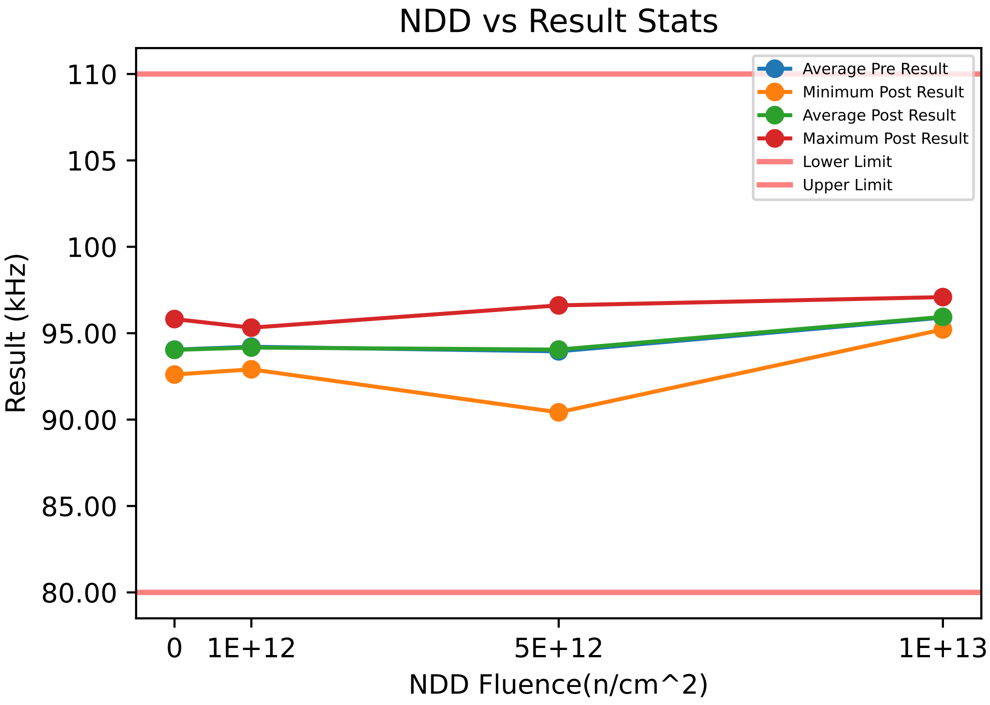
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

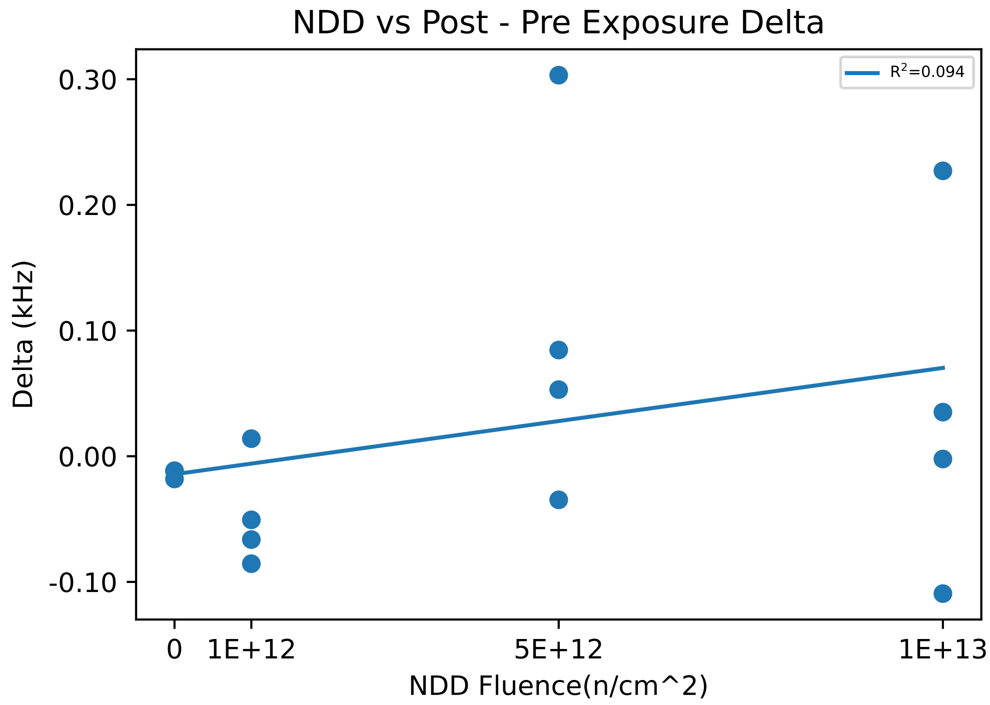
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.999	-0.0032
2	1e+12	NDD	100	100	-0.0026
3	1e+12	NDD	100	100	-0.0024
4	1e+12	NDD	100	99.997	-0.0054
5	5e+12	NDD	100	99.999	-0.0026
6	5e+12	NDD	100	99.999	-0.0025
7	5e+12	NDD	100	99.999	-0.0034
8	5e+12	NDD	100	100	-0.0028
9	1e+13	NDD	100	100	-0.0031
10	1e+13	NDD	100	99.999	-0.0033
11	1e+13	NDD	100	100	0.0003
12	1e+13	NDD	100	99.999	-0.0038
13	0	CORRELATION	100	99.999	-0.0042
14	0	CORRELATION	100	100	-0.0006
15	0	CORRELATION	100	100	-0.0007

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.0011015	99.999	100	100	0.00095394	-0.0042	-0.0018333	-0.0006	0.0020502
1e+12	100	100	100	0.00055	99.997	100	100	0.0018062	-0.0054	-0.0034	-0.0024	0.001376
5e+12	100	100	100	0.0010279	99.999	100	100	0.00092511	-0.0034	-0.002825	-0.0025	0.00040311
1e+13	100	100	100	0.0013614	99.999	100	100	0.00089954	-0.0038	-0.002475	0.0003	0.0018733

Device Test: 20.73 LEVEL|FREQ/RT/5/5/0/1000/5/100kHz//@FSW_EXT_RT_A





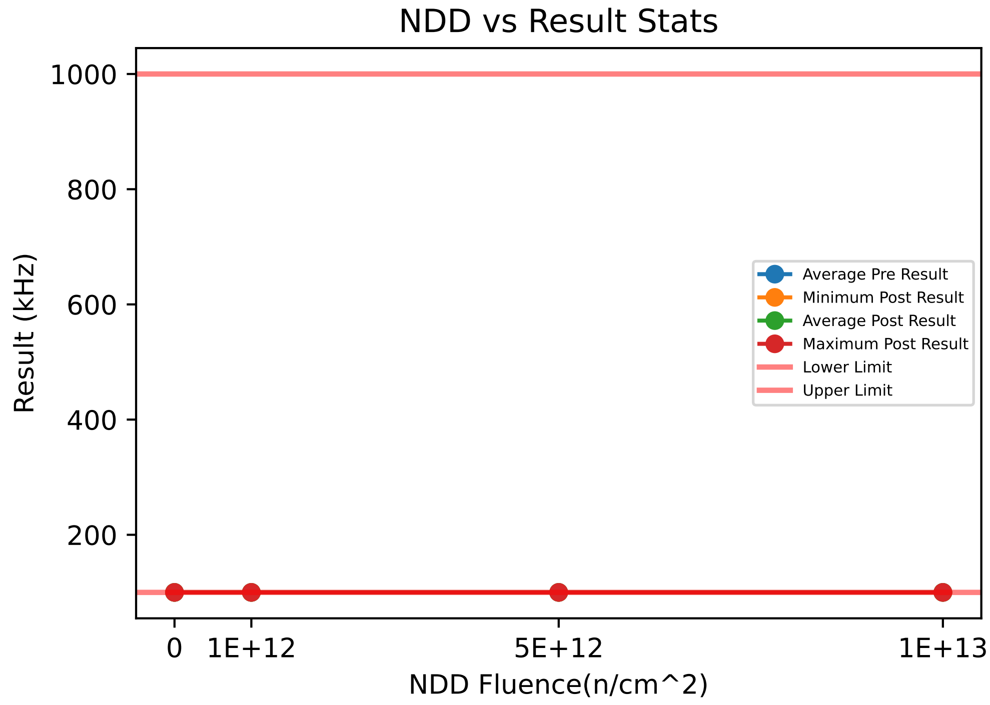
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

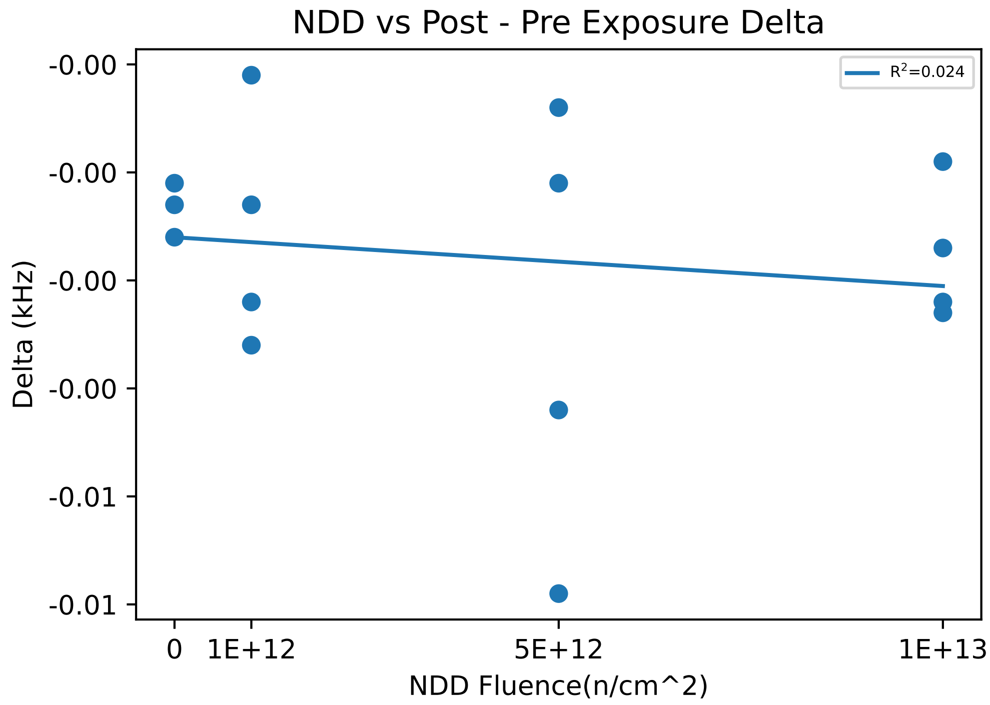
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.387	95.321	-0.0663
2	1e+12	NDD	92.96	92.909	-0.0506
3	1e+12	NDD	93.932	93.946	0.014
4	1e+12	NDD	94.586	94.501	-0.0855
5	5e+12	NDD	90.336	90.421	0.0845
6	5e+12	NDD	92.74	92.793	0.053
7	5e+12	NDD	96.079	96.382	0.3032
8	5e+12	NDD	96.644	96.61	-0.0347
9	1e+13	NDD	95.402	95.629	0.2271
10	1e+13	NDD	95.799	95.835	0.0351
11	1e+13	NDD	97.198	97.089	-0.1093
12	1e+13	NDD	95.221	95.218	-0.0022
13	0	CORRELATION	93.692	93.681	-0.0115
14	0	CORRELATION	95.831	95.819	-0.0119
15	0	CORRELATION	92.625	92.607	-0.0181

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.625	94.049	95.831	1.6324	92.607	94.035	95.819	1.635	-0.0181	-0.013833	-0.0115	0.0037005
1e+12	92.96	94.216	95.387	1.0275	92.909	94.169	95.321	1.0122	-0.0855	-0.0471	0.014	0.043161
5e+12	90.336	93.95	96.644	2.9617	90.421	94.051	96.61	2.9856	-0.0347	0.1015	0.3032	0.14361
1e+13	95.221	95.905	97.198	0.89538	95.218	95.943	97.089	0.80595	-0.1093	0.037675	0.2271	0.14033

Device Test: 20.74 LEVEL|FREQ/SYNC/5/5/0/1000/5/100kHz//@FREQ_SYNC_EXT





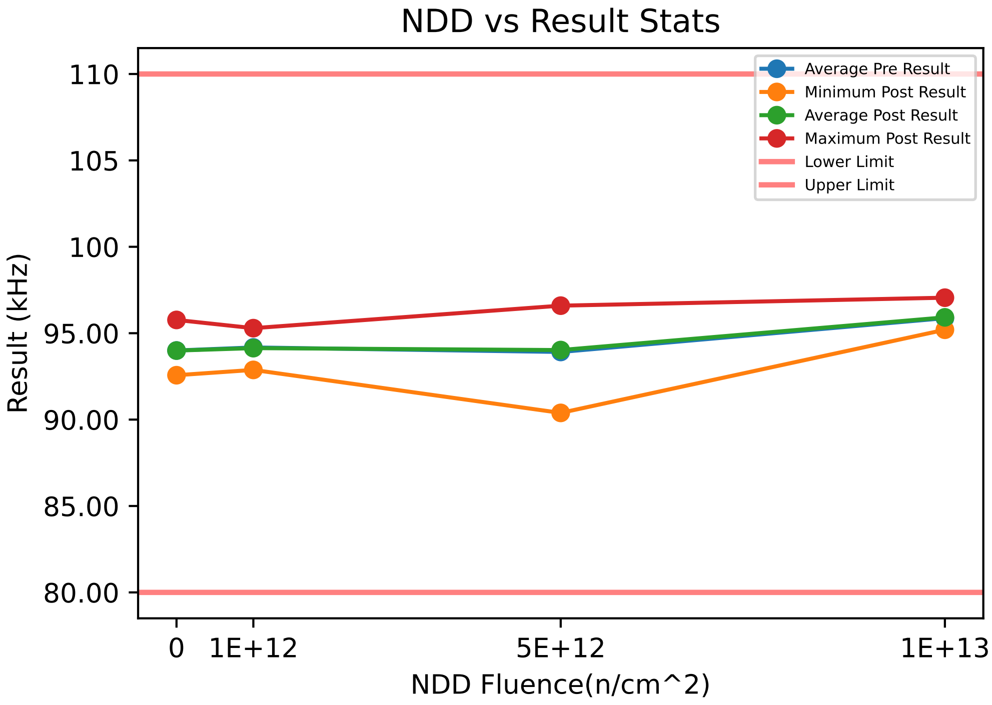
Test Results (Lower Limit = 100.0,
Upper Limit = 1000.0 (kHz))

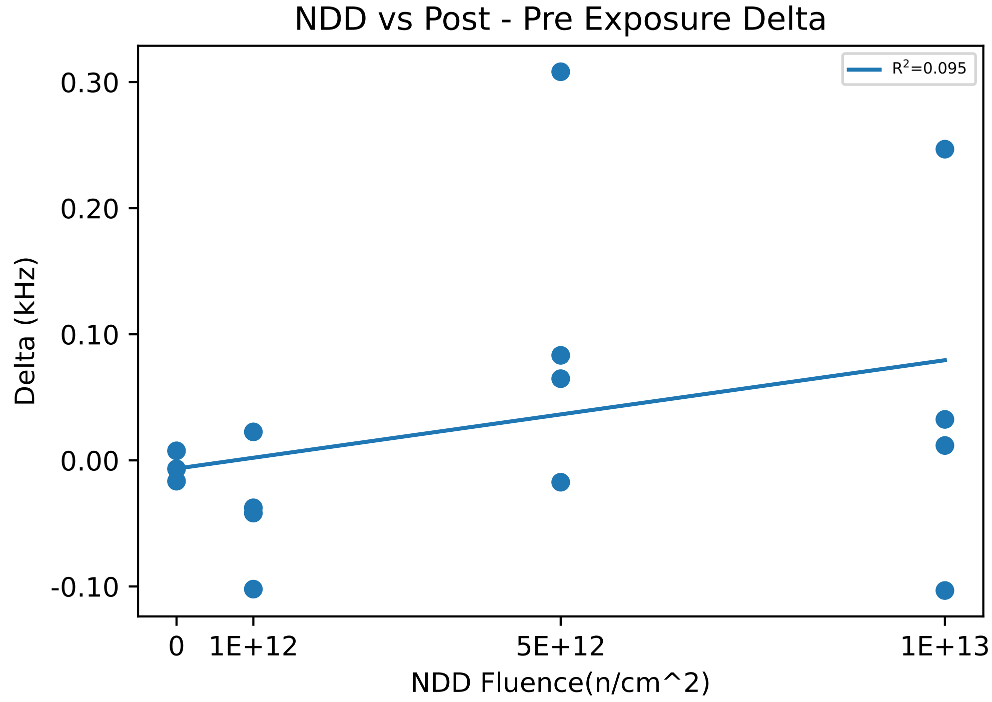
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.998	-0.0036
2	1e+12	NDD	100	99.999	-0.0023
3	1e+12	NDD	100	100	-0.0011
4	1e+12	NDD	100	99.999	-0.0032
5	5e+12	NDD	100	99.999	-0.0042
6	5e+12	NDD	100	99.999	-0.0021
7	5e+12	NDD	100	99.997	-0.0059
8	5e+12	NDD	100	100	-0.0014
9	1e+13	NDD	100	99.999	-0.0027
10	1e+13	NDD	100	99.997	-0.0033
11	1e+13	NDD	100	100	-0.0019
12	1e+13	NDD	100	100	-0.0032
13	0	CORRELATION	100	99.999	-0.0023
14	0	CORRELATION	100	99.999	-0.0026
15	0	CORRELATION	100	99.999	-0.0021

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.00015275	99.999	99.999	99.999	0.0001	-0.0026	-0.0023333	-0.0021	0.00025166
1e+12	100	100	100	0.00062383	99.998	99.999	100	0.0013124	-0.0036	-0.00255	-0.0011	0.0011091
5e+12	100	100	100	0.00094296	99.997	99.999	100	0.0013124	-0.0059	-0.0034	-0.0014	0.0020478
1e+13	100	100	100	0.0013401	99.997	99.999	100	0.0015503	-0.0033	-0.002775	-0.0019	0.00063966

Device Test: 20.75 LEVEL|FREQ/RT/12/12/0/1000/5/100kHz//@FSW_EXT_RT_A





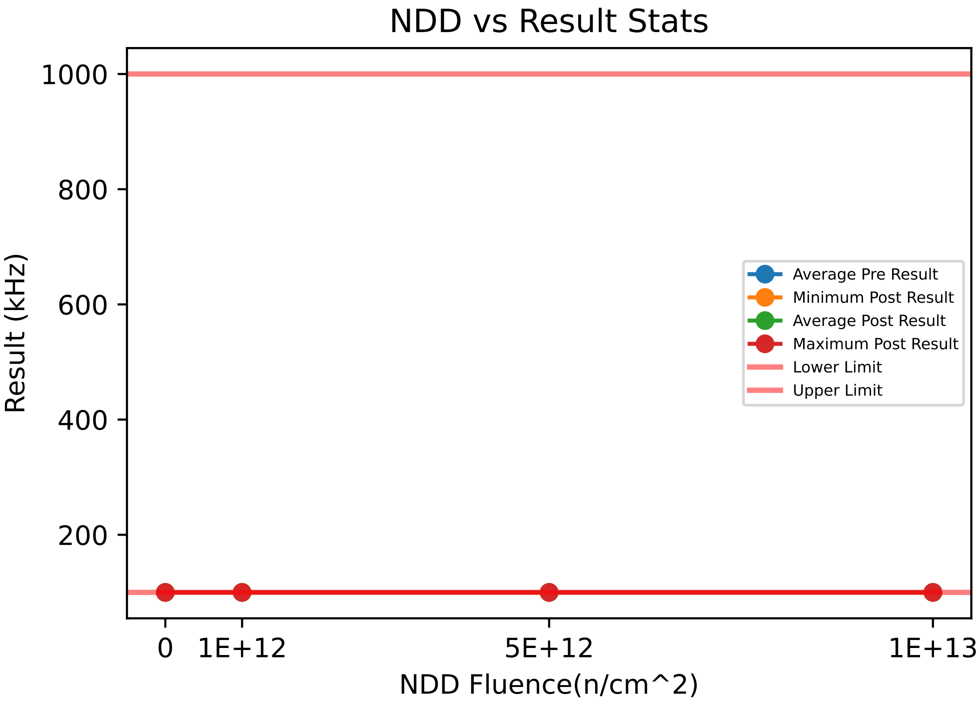
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

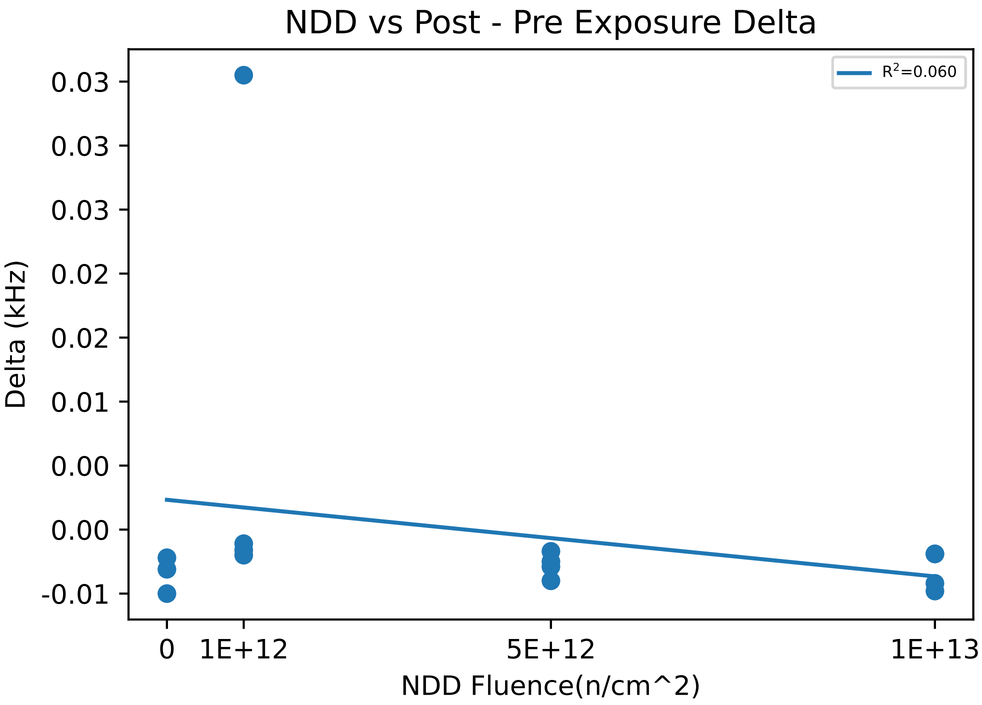
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.333	95.291	-0.0418
2	1e+12	NDD	92.914	92.876	-0.0376
3	1e+12	NDD	93.893	93.915	0.0226
4	1e+12	NDD	94.563	94.461	-0.1021
5	5e+12	NDD	90.305	90.388	0.0833
6	5e+12	NDD	92.698	92.763	0.0648
7	5e+12	NDD	96.043	96.352	0.3082
8	5e+12	NDD	96.611	96.594	-0.0173
9	1e+13	NDD	95.36	95.607	0.2468
10	1e+13	NDD	95.773	95.806	0.0325
11	1e+13	NDD	97.158	97.055	-0.1032
12	1e+13	NDD	95.188	95.2	0.0118
13	0	CORRELATION	93.638	93.645	0.0076
14	0	CORRELATION	95.775	95.768	-0.0067
15	0	CORRELATION	92.585	92.568	-0.0165

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.585	93.999	95.775	1.6254	92.568	93.994	95.768	1.6281	-0.0165	-0.0052	0.0076	0.01212
1e+12	92.914	94.176	95.333	1.0268	92.876	94.136	95.291	1.0127	-0.1021	-0.039725	0.0226	0.050937
5e+12	90.305	93.914	96.611	2.9616	90.388	94.024	96.594	2.9907	-0.0173	0.10975	0.3082	0.13934
1e+13	95.188	95.87	97.158	0.89316	95.2	95.917	97.055	0.79945	-0.1032	0.046975	0.2468	0.14598

Device Test: 20.76 LEVEL|FREQ/SYNC/12/12/0/1000/5/100kHz//@FREQ_SYNC_EXT





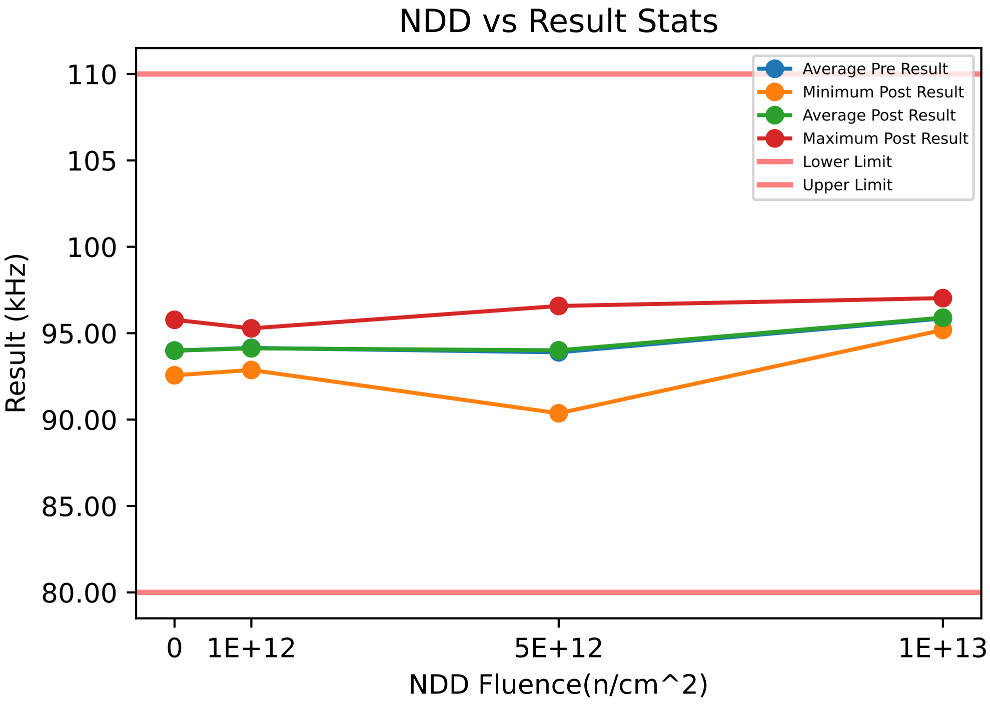
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

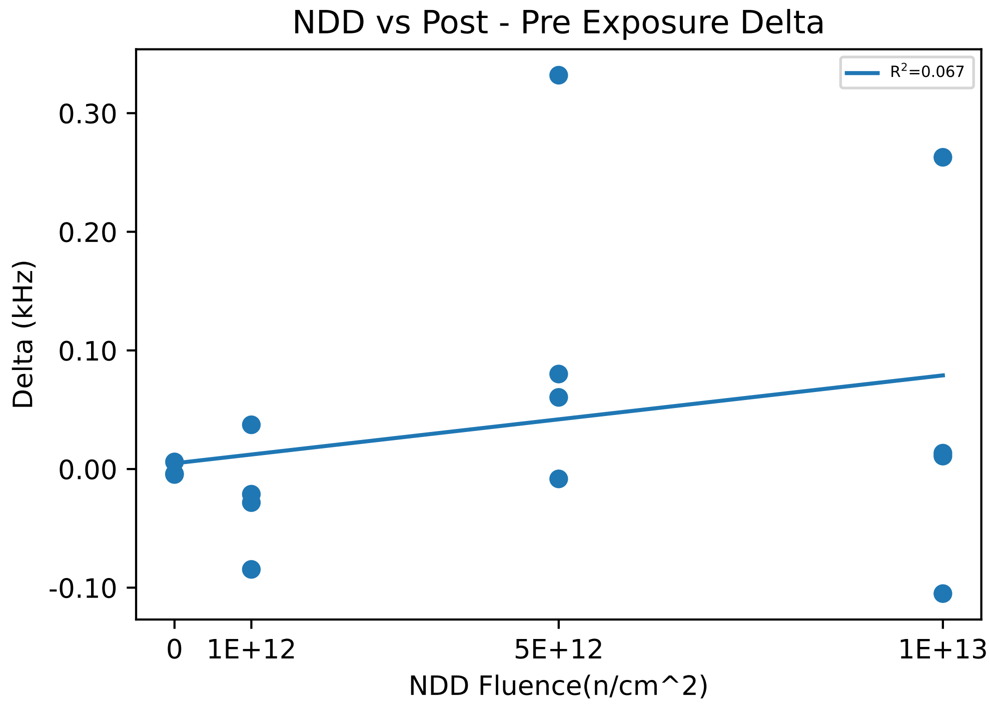
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.999	-0.0016
2	1e+12	NDD	99.964	99.999	0.0355
3	1e+12	NDD	100	100	-0.002
4	1e+12	NDD	100	99.999	-0.0011
5	5e+12	NDD	100	100	-0.0017
6	5e+12	NDD	100	99.999	-0.0025
7	5e+12	NDD	100	99.999	-0.0029
8	5e+12	NDD	100	99.999	-0.004
9	1e+13	NDD	100	99.999	-0.0048
10	1e+13	NDD	100	99.999	-0.0019
11	1e+13	NDD	100	100	-0.0019
12	1e+13	NDD	100	99.999	-0.0042
13	0	CORRELATION	100	99.997	-0.005
14	0	CORRELATION	100	100	-0.0022
15	0	CORRELATION	100	99.999	-0.0031

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.00020817	99.997	99.999	100	0.0014526	-0.005	-0.0034333	-0.0022	0.0014295
1e+12	99.964	99.992	100	0.018679	99.999	99.999	100	0.00099499	-0.002	0.0077	0.0355	0.018537
5e+12	100	100	100	0.00066521	99.999	99.999	100	0.00065574	-0.004	-0.002775	-0.0017	0.00095699
1e+13	100	100	100	0.0011916	99.999	99.999	100	0.00080416	-0.0048	-0.0032	-0.0019	0.001521

Device Test: 20.77 LEVEL|FREQ/RT/14/14/0/1000/5/100kHz//@FSW_EXT_RT_A





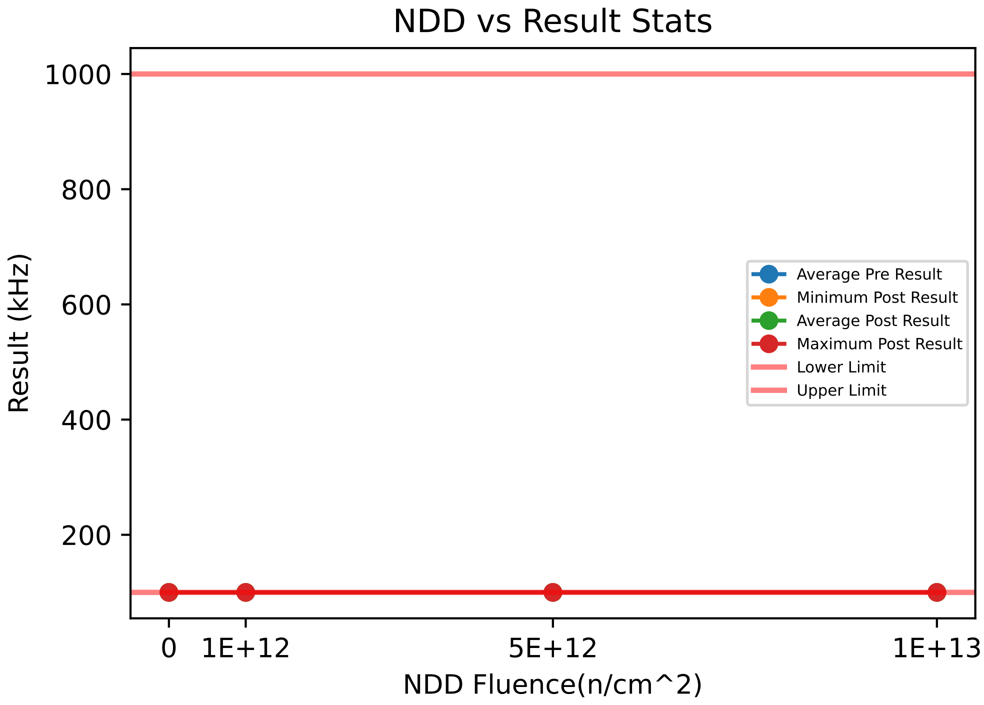
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

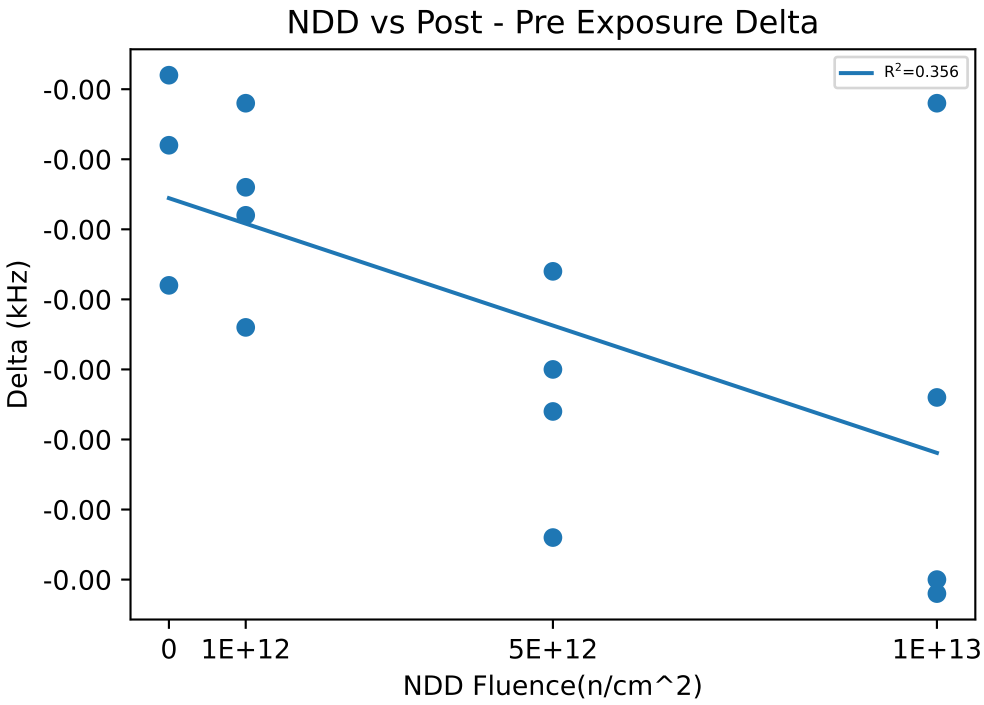
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	95.302	95.281	-0.0212
2	1e+12	NDD	92.898	92.87	-0.0283
3	1e+12	NDD	93.872	93.909	0.0373
4	1e+12	NDD	94.523	94.438	-0.0846
5	5e+12	NDD	90.287	90.367	0.0801
6	5e+12	NDD	92.69	92.751	0.0604
7	5e+12	NDD	96.013	96.345	0.332
8	5e+12	NDD	96.583	96.575	-0.0083
9	1e+13	NDD	95.338	95.601	0.2628
10	1e+13	NDD	95.765	95.778	0.0134
11	1e+13	NDD	97.136	97.031	-0.105
12	1e+13	NDD	95.178	95.189	0.0109
13	0	CORRELATION	93.639	93.635	-0.004
14	0	CORRELATION	95.769	95.775	0.006
15	0	CORRELATION	92.57	92.565	-0.0046

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.57	93.993	95.769	1.6288	92.565	93.992	95.775	1.6345	-0.0046	-0.00086667	0.006	0.0059543
1e+12	92.898	94.149	95.302	1.0181	92.87	94.124	95.281	1.0091	-0.0846	-0.0242	0.0373	0.049854
5e+12	90.287	93.893	96.583	2.9543	90.367	94.009	96.575	2.9939	-0.0083	0.11605	0.332	0.14887
1e+13	95.178	95.854	97.136	0.88967	95.189	95.9	97.031	0.79355	-0.105	0.045525	0.2628	0.15502

Device Test: 20.78 LEVEL|FREQ/SYNC/14/14/0/1000/5/100kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

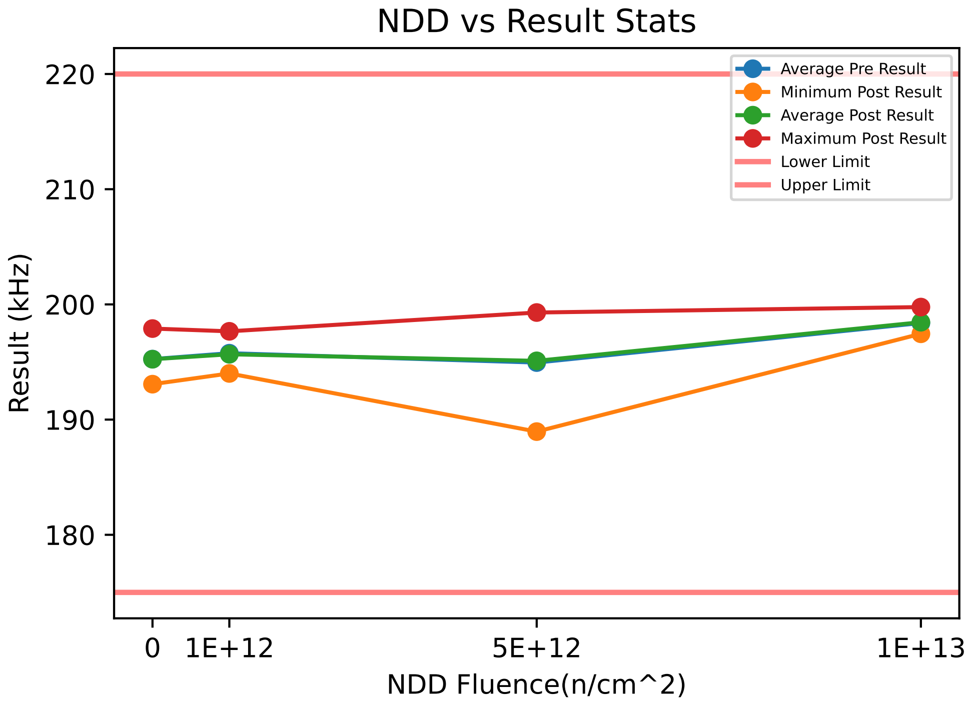
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

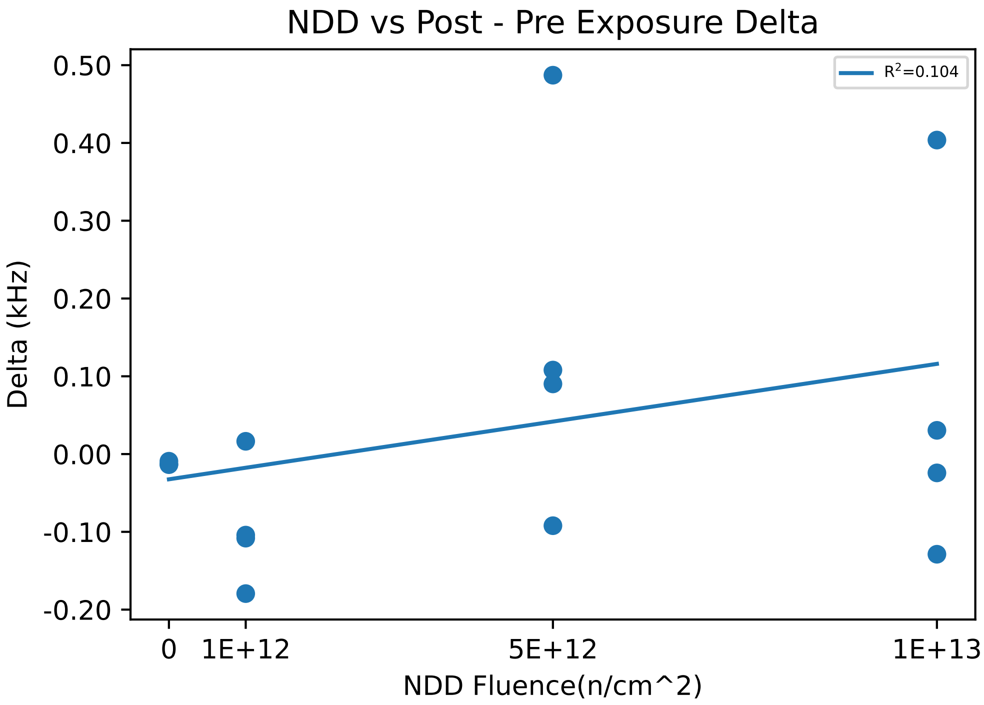
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	100	99.999	-0.0019
2	1e+12	NDD	100	100	-0.0027
3	1e+12	NDD	100	100	-0.0011
4	1e+12	NDD	100	99.999	-0.0017
5	5e+12	NDD	100	100	-0.003
6	5e+12	NDD	100	100	-0.0023
7	5e+12	NDD	100	99.998	-0.0042
8	5e+12	NDD	100	99.999	-0.0033
9	1e+13	NDD	100	99.999	-0.0046
10	1e+13	NDD	100	99.998	-0.0045
11	1e+13	NDD	100	99.999	-0.0032
12	1e+13	NDD	100	100	-0.0011
13	0	CORRELATION	100	99.999	-0.0014
14	0	CORRELATION	100	100	-0.0009
15	0	CORRELATION	100	100	-0.0024

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100	100	100	0.0013317	99.999	100	100	0.00085049	-0.0024	-0.0015667	-0.0009	0.00076376
1e+12	100	100	100	0.0010801	99.999	100	100	0.00094692	-0.0027	-0.00185	-0.0011	0.00066081
5e+12	100	100	100	0.00049917	99.998	99.999	100	0.0012366	-0.0042	-0.0032	-0.0023	0.0007874
1e+13	100	100	100	0.0010243	99.998	99.999	100	0.00094296	-0.0046	-0.00335	-0.0011	0.0016299

Device Test: 20.79 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/200kHz//@FSW_EXT_RT_B


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

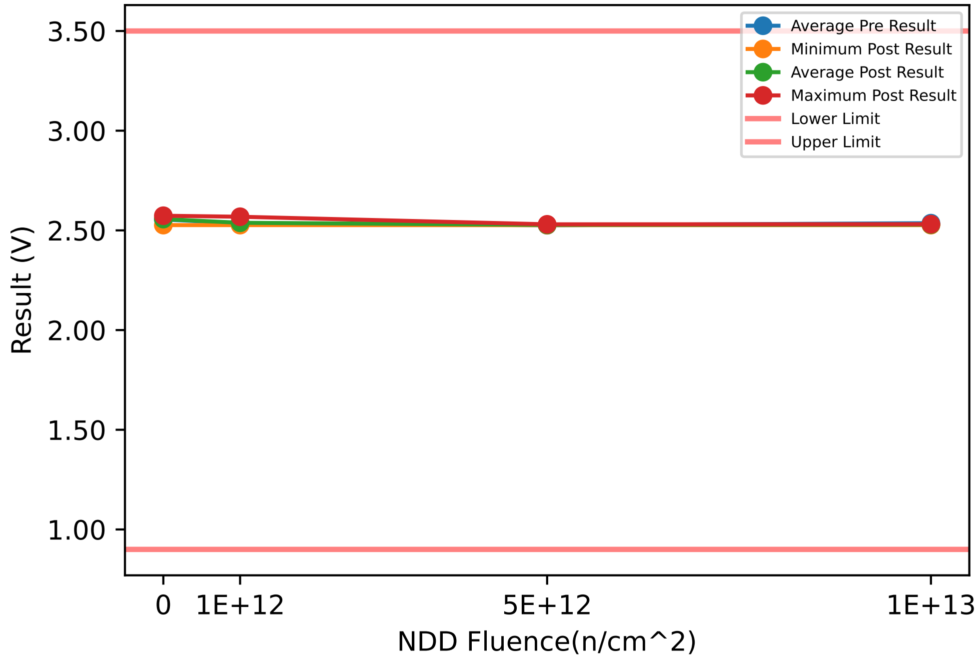
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

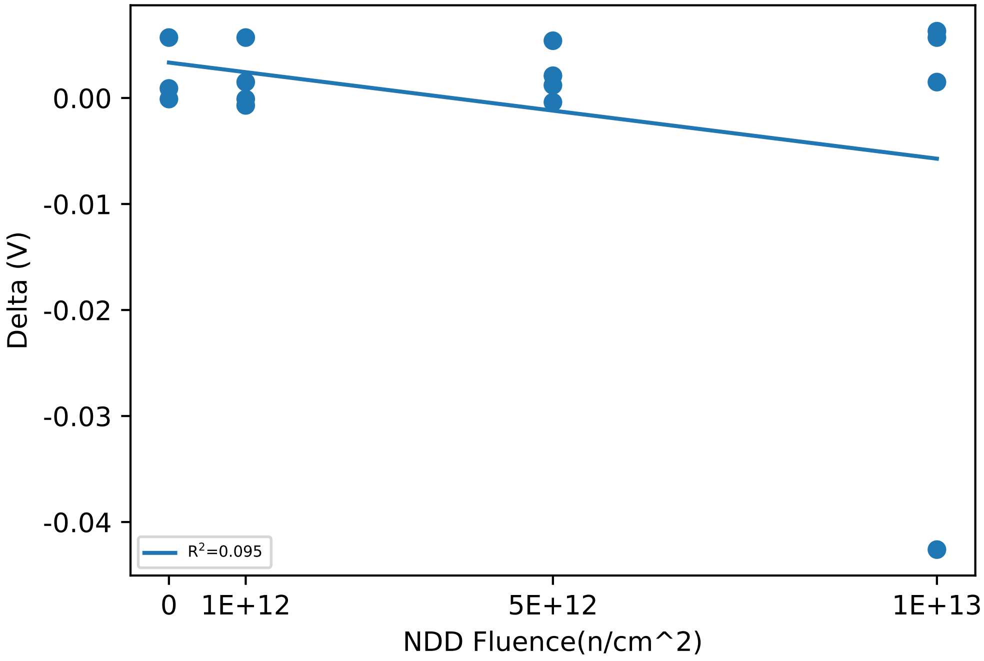
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.77	197.66	-0.1081
2	1e+12	NDD	194.11	194.01	-0.1042
3	1e+12	NDD	195.06	195.07	0.0164
4	1e+12	NDD	196.11	195.93	-0.1794
5	5e+12	NDD	188.87	188.96	0.0902
6	5e+12	NDD	193.42	193.53	0.108
7	5e+12	NDD	198.13	198.61	0.4871
8	5e+12	NDD	199.39	199.29	-0.0921
9	1e+13	NDD	197.98	198.38	0.4037
10	1e+13	NDD	198.18	198.21	0.0305
11	1e+13	NDD	199.9	199.77	-0.1288
12	1e+13	NDD	197.47	197.45	-0.0242
13	0	CORRELATION	194.76	194.74	-0.0136
14	0	CORRELATION	197.92	197.9	-0.0132
15	0	CORRELATION	193.08	193.07	-0.0092

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	193.08	195.25	197.92	2.4533	193.07	195.24	197.9	2.4516	-0.0136	-0.012	-0.0092	0.0024331
1e+12	194.11	195.76	197.77	1.5689	194.01	195.67	197.66	1.5455	-0.1794	-0.093825	0.0164	0.081208
5e+12	188.87	194.95	199.39	4.7993	188.96	195.1	199.29	4.8348	-0.0921	0.1483	0.4871	0.24329
1e+13	197.47	198.38	199.9	1.0519	197.45	198.45	199.77	0.96579	-0.1288	0.0703	0.4037	0.23188

Device Test: 20.8 LEVEL|HIGH_LEVEL/SYNC/5.5/5.5/0/0/4.5/500kHz//@SYNC_VIH_TH_HIGH_4P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.9, Upper Limit = 3.5 (V))

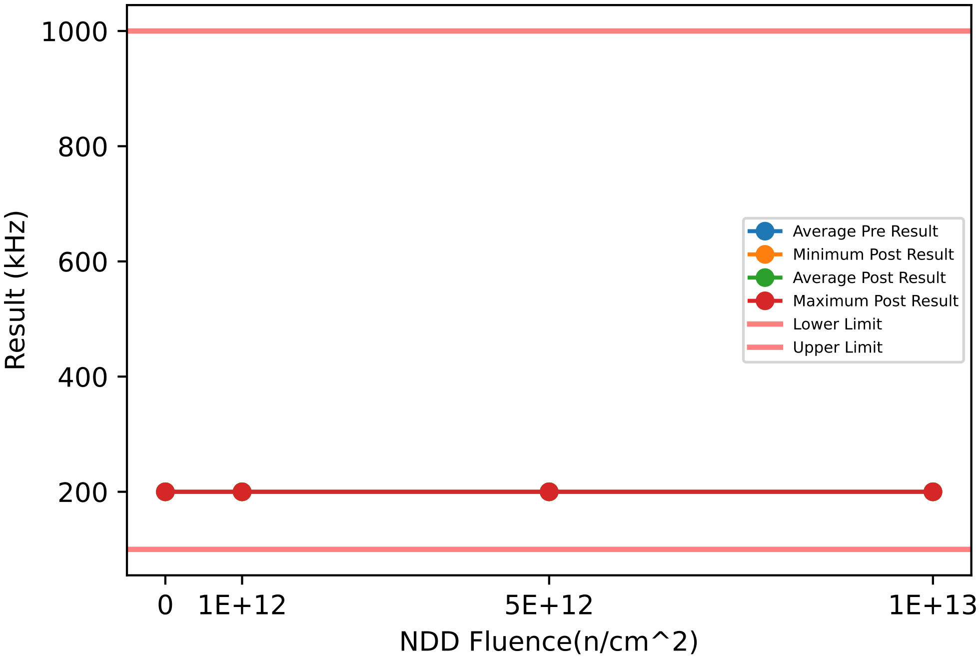
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.5691	2.5684	-0.0007
2	1e+12	NDD	2.5257	2.5272	0.0015
3	1e+12	NDD	2.5247	2.5304	0.0057
4	1e+12	NDD	2.5266	2.5265	-0.0001
5	5e+12	NDD	2.526	2.5272	0.0012
6	5e+12	NDD	2.525	2.5304	0.0054
7	5e+12	NDD	2.5266	2.5262	-0.0004
8	5e+12	NDD	2.5254	2.5275	0.0021
9	1e+13	NDD	2.5247	2.531	0.0063
10	1e+13	NDD	2.5691	2.5265	-0.0426
11	1e+13	NDD	2.526	2.5275	0.0015
12	1e+13	NDD	2.525	2.5307	0.0057
13	0	CORRELATION	2.5266	2.5265	-0.0001
14	0	CORRELATION	2.5691	2.57	0.0009
15	0	CORRELATION	2.5678	2.5735	0.0057

Test Statistics (V)

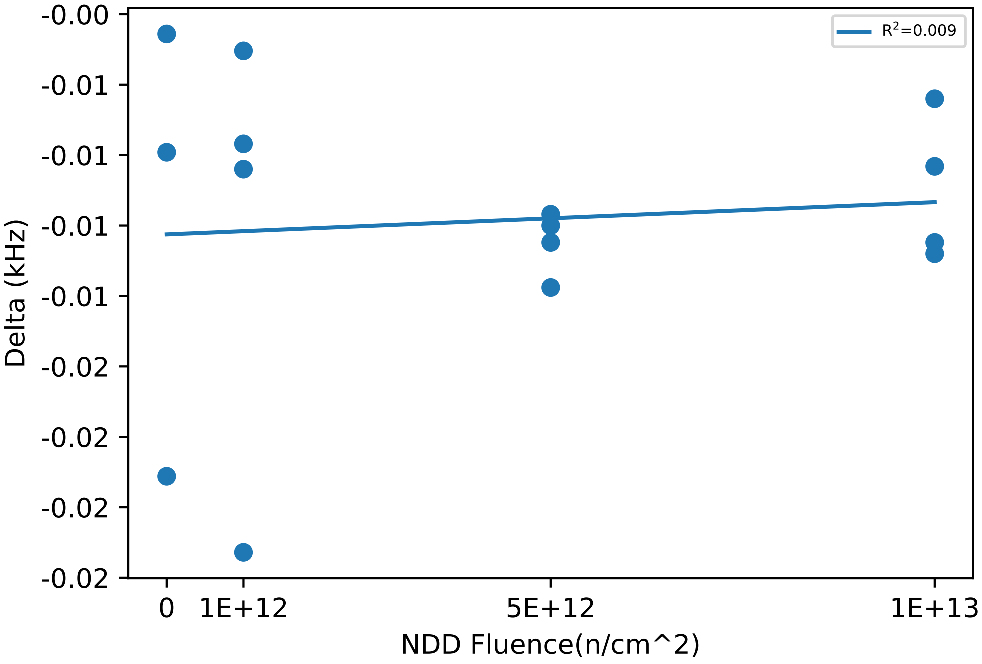
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5266	2.5545	2.5691	0.024171	2.5265	2.5567	2.5735	0.026184	-0.0001	0.0021667	0.0057	0.0031005
1e+12	2.5247	2.5365	2.5691	0.021731	2.5265	2.5381	2.5684	0.020255	-0.0007	0.0016	0.0057	0.0028868
5e+12	2.525	2.5257	2.5266	0.0007	2.5262	2.5278	2.5304	0.0018044	-0.0004	0.002075	0.0054	0.0024459
1e+13	2.5247	2.5362	2.5691	0.02194	2.5265	2.5289	2.531	0.0022633	-0.0426	-0.007275	0.0063	0.023647

Device Test: 20.80 LEVEL|FREQ/SYNC/4.5/4.5/0/1000/4.5/200kHz//@FREQ_SYNC_EXT

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



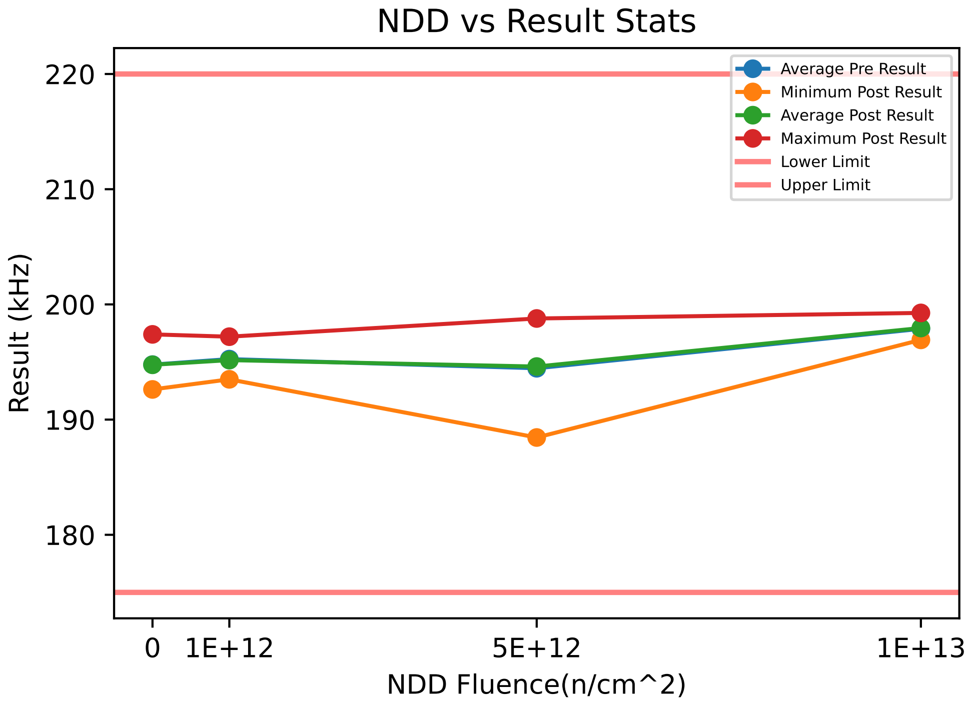
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

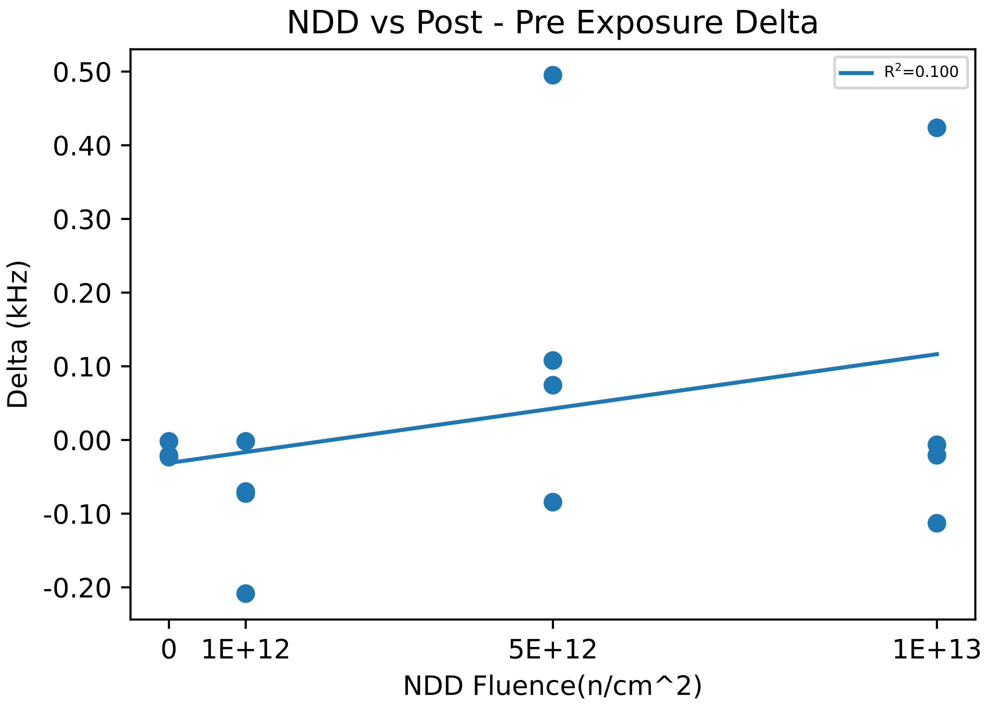
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200	200	-0.0038
2	1e+12	NDD	200	200	-0.0071
3	1e+12	NDD	200.01	200	-0.008
4	1e+12	NDD	200.01	199.99	-0.0216
5	5e+12	NDD	200.01	200	-0.01
6	5e+12	NDD	200.01	200	-0.0096
7	5e+12	NDD	200.01	200	-0.0122
8	5e+12	NDD	200.01	200	-0.0106
9	1e+13	NDD	200.01	200	-0.0106
10	1e+13	NDD	200	199.99	-0.011
11	1e+13	NDD	200.01	200	-0.0079
12	1e+13	NDD	200.01	200	-0.0055
13	0	CORRELATION	200.01	200	-0.0074
14	0	CORRELATION	200.01	200	-0.0032
15	0	CORRELATION	200.01	200	-0.0189

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200.01	200.01	200.01	0.0050478	200	200	200	0.0038423	-0.0189	-0.0098333	-0.0032	0.0081279
1e+12	200	200.01	200.01	0.0044855	199.99	200	200	0.0035911	-0.0216	-0.010125	-0.0038	0.0078602
5e+12	200.01	200.01	200.01	0.0032633	200	200	200	0.0028253	-0.0122	-0.0106	-0.0096	0.0011431
1e+13	200	200.01	200.01	0.0029218	199.99	200	200	0.005084	-0.011	-0.00875	-0.0055	0.0025671

Device Test: 20.81 LEVEL|FREQ/RT/5/5/0/1000/5/200kHz//@FSW_EXT_RT_B





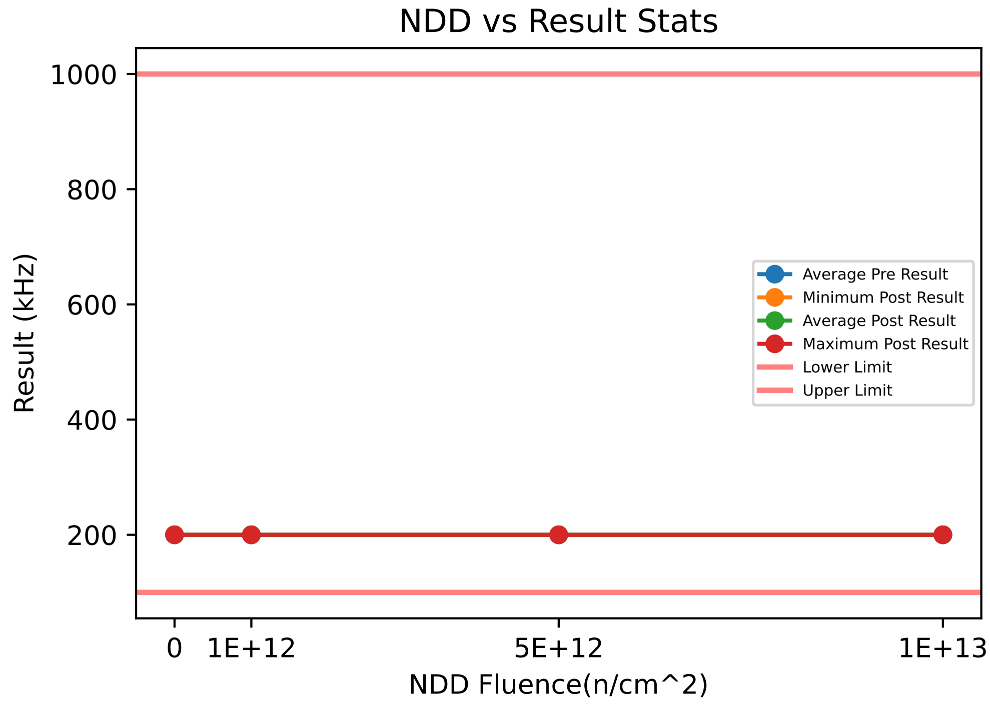
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

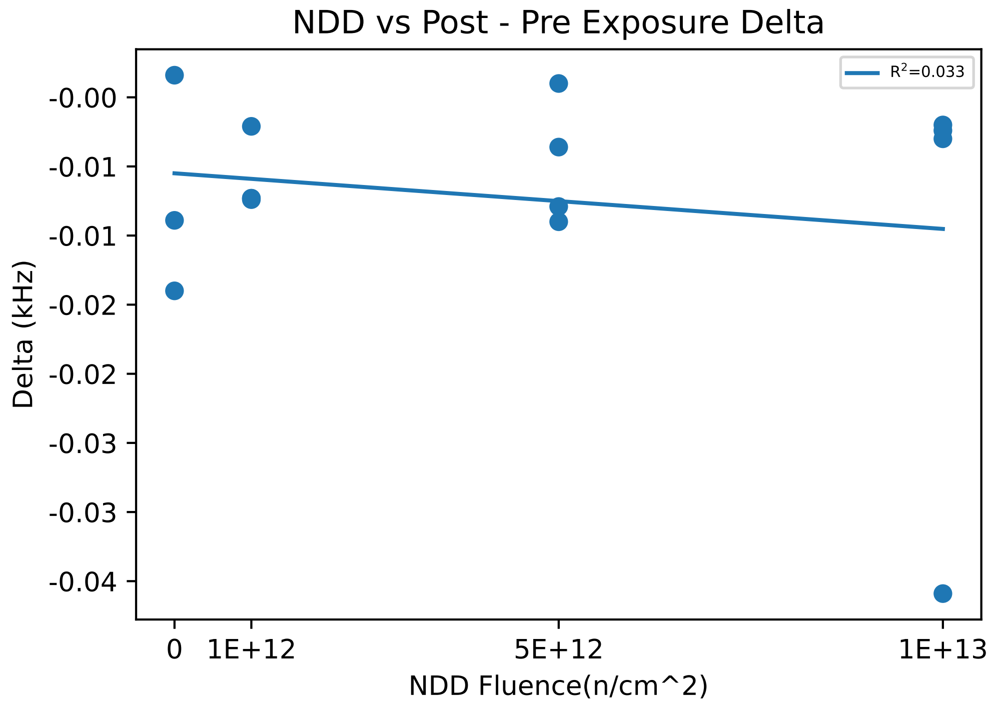
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.27	197.2	-0.07
2	1e+12	NDD	193.57	193.5	-0.0727
3	1e+12	NDD	194.57	194.57	-0.0019
4	1e+12	NDD	195.6	195.39	-0.2085
5	5e+12	NDD	188.34	188.45	0.1079
6	5e+12	NDD	192.93	193	0.0744
7	5e+12	NDD	197.7	198.19	0.4951
8	5e+12	NDD	198.86	198.78	-0.0844
9	1e+13	NDD	197.49	197.92	0.4237
10	1e+13	NDD	197.72	197.7	-0.0208
11	1e+13	NDD	199.37	199.26	-0.113
12	1e+13	NDD	196.93	196.92	-0.0065
13	0	CORRELATION	194.28	194.26	-0.0209
14	0	CORRELATION	197.4	197.4	-0.0019
15	0	CORRELATION	192.64	192.62	-0.0233

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.64	194.77	197.4	2.4173	192.62	194.76	197.4	2.4287	-0.0233	-0.015367	-0.0019	0.011724
1e+12	193.57	195.25	197.27	1.5792	193.5	195.16	197.2	1.5626	-0.2085	-0.088275	-0.0019	0.086586
5e+12	188.34	194.46	198.86	4.8189	188.45	194.6	198.78	4.8568	-0.0844	0.14825	0.4951	0.24598
1e+13	196.93	197.88	199.37	1.0505	196.92	197.95	199.26	0.97256	-0.113	0.07085	0.4237	0.23992

Device Test: 20.82 LEVEL|FREQ/SYNC/5/5/0/1000/5/200kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

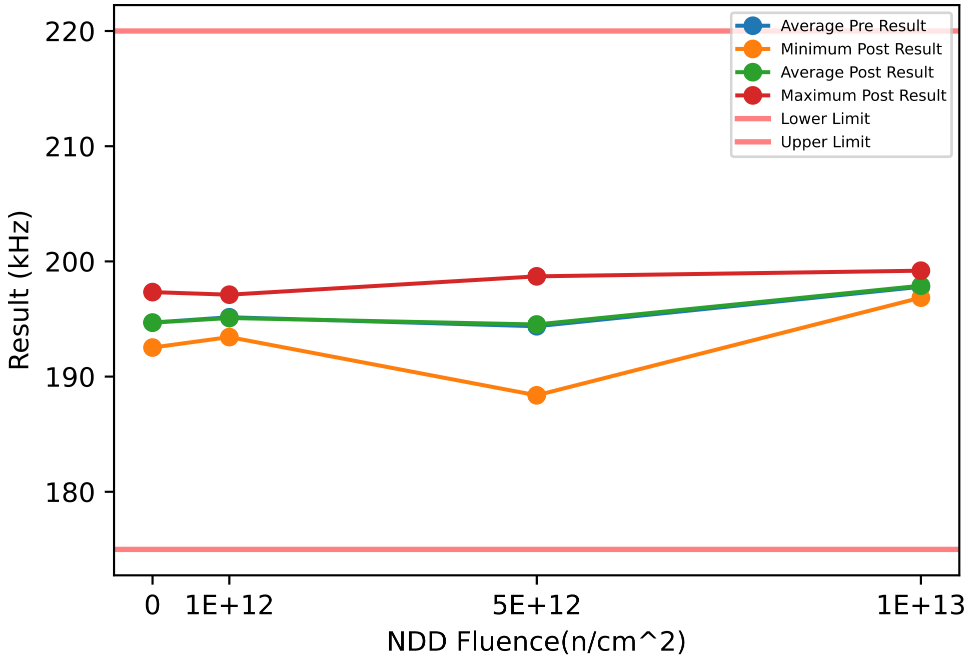
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

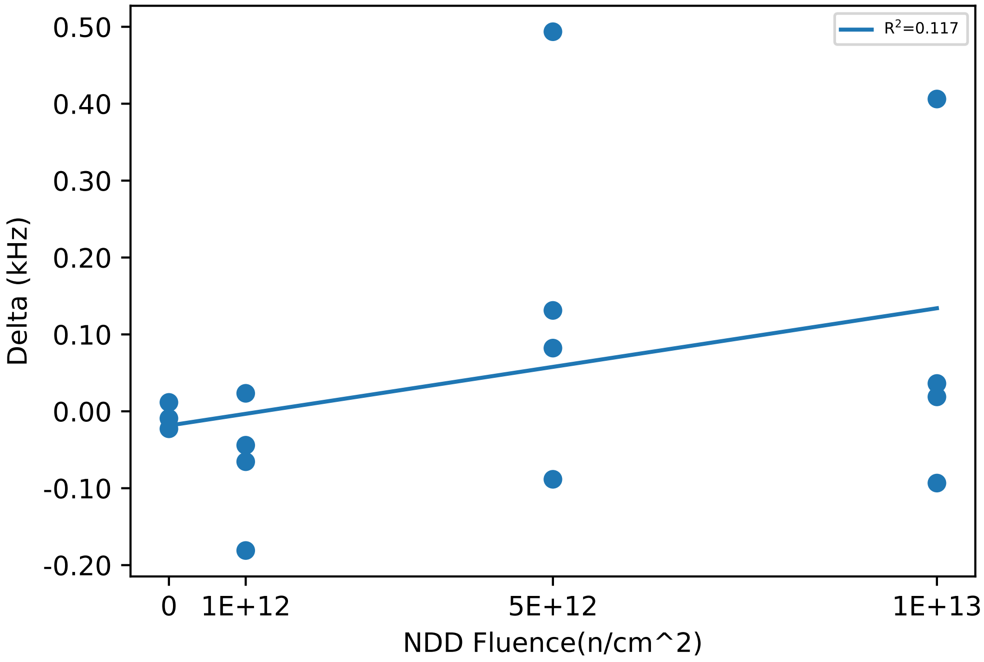
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200.01	200	-0.0124
2	1e+12	NDD	200.01	200	-0.0123
3	1e+12	NDD	200.01	200	-0.0123
4	1e+12	NDD	200	200	-0.0071
5	5e+12	NDD	200	200	-0.0086
6	5e+12	NDD	200.01	200	-0.004
7	5e+12	NDD	200.01	200	-0.014
8	5e+12	NDD	200.01	200	-0.0129
9	1e+13	NDD	200.01	200	-0.008
10	1e+13	NDD	200.01	199.97	-0.0409
11	1e+13	NDD	200.01	200	-0.007
12	1e+13	NDD	200	200	-0.0074
13	0	CORRELATION	200.01	199.99	-0.019
14	0	CORRELATION	200.01	200	-0.0139
15	0	CORRELATION	200.01	200	-0.0034

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200.01	200.01	200.01	0.0024249	199.99	200	200	0.0063095	-0.019	-0.0121	-0.0034	0.0079542
1e+12	200	200.01	200.01	0.0027598	200	200	200	0.00053774	-0.0124	-0.011025	-0.0071	0.0026171
5e+12	200	200.01	200.01	0.0028172	200	200	200	0.0034529	-0.014	-0.009875	-0.004	0.0045573
1e+13	200	200.01	200.01	0.0025495	199.97	199.99	200	0.016764	-0.0409	-0.015825	-0.007	0.016722

Device Test: 20.83 LEVEL|FREQ/RT/12/12/0/1000/5/200kHz//@FSW_EXT_RT_B


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

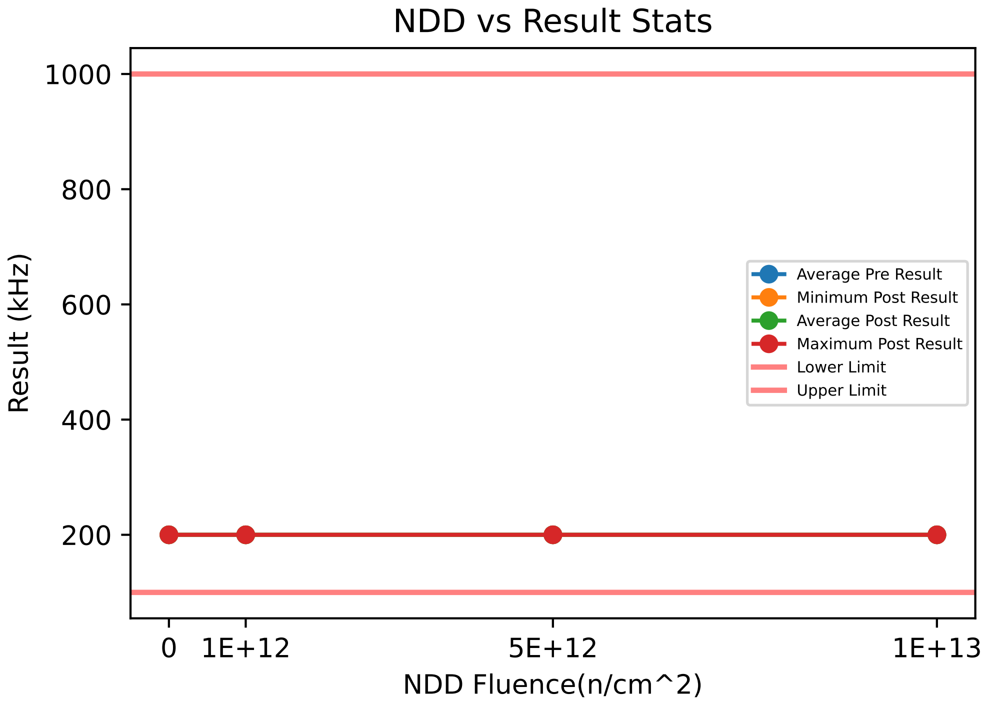
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

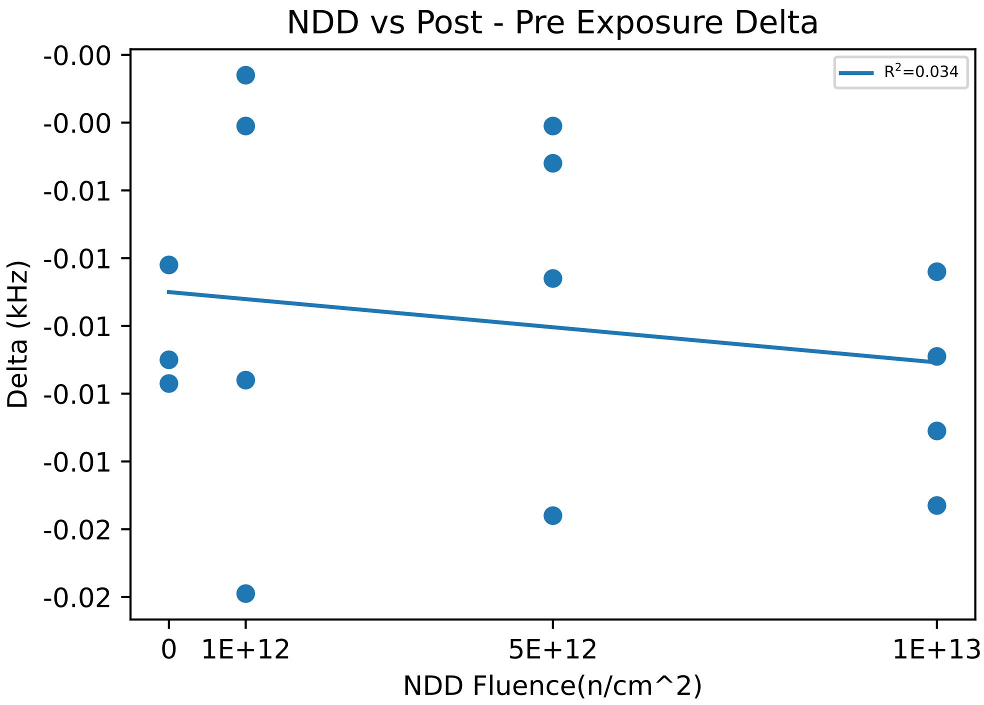
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.18	197.11	-0.0655
2	1e+12	NDD	193.47	193.43	-0.0441
3	1e+12	NDD	194.48	194.5	0.0234
4	1e+12	NDD	195.48	195.3	-0.181
5	5e+12	NDD	188.24	188.37	0.1312
6	5e+12	NDD	192.83	192.91	0.0822
7	5e+12	NDD	197.62	198.11	0.4936
8	5e+12	NDD	198.79	198.7	-0.0884
9	1e+13	NDD	197.44	197.85	0.4061
10	1e+13	NDD	197.63	197.66	0.0362
11	1e+13	NDD	199.29	199.19	-0.0933
12	1e+13	NDD	196.83	196.85	0.0188
13	0	CORRELATION	194.2	194.19	-0.0092
14	0	CORRELATION	197.32	197.33	0.0116
15	0	CORRELATION	192.54	192.52	-0.0227

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.54	194.69	197.32	2.426	192.52	194.68	197.33	2.4433	-0.0227	-0.0067667	0.0116	0.017279
1e+12	193.47	195.15	197.18	1.578	193.43	195.08	197.11	1.5519	-0.181	-0.0668	0.0234	0.085039
5e+12	188.24	194.37	198.79	4.8302	188.37	194.52	198.7	4.8557	-0.0884	0.15465	0.4936	0.24479
1e+13	196.83	197.8	199.29	1.049	196.85	197.89	199.19	0.97083	-0.0933	0.09195	0.4061	0.21715

Device Test: 20.84 LEVEL|FREQ/SYNC/12/12/0/1000/5/200kHz//@FREQ_SYNC_EXT





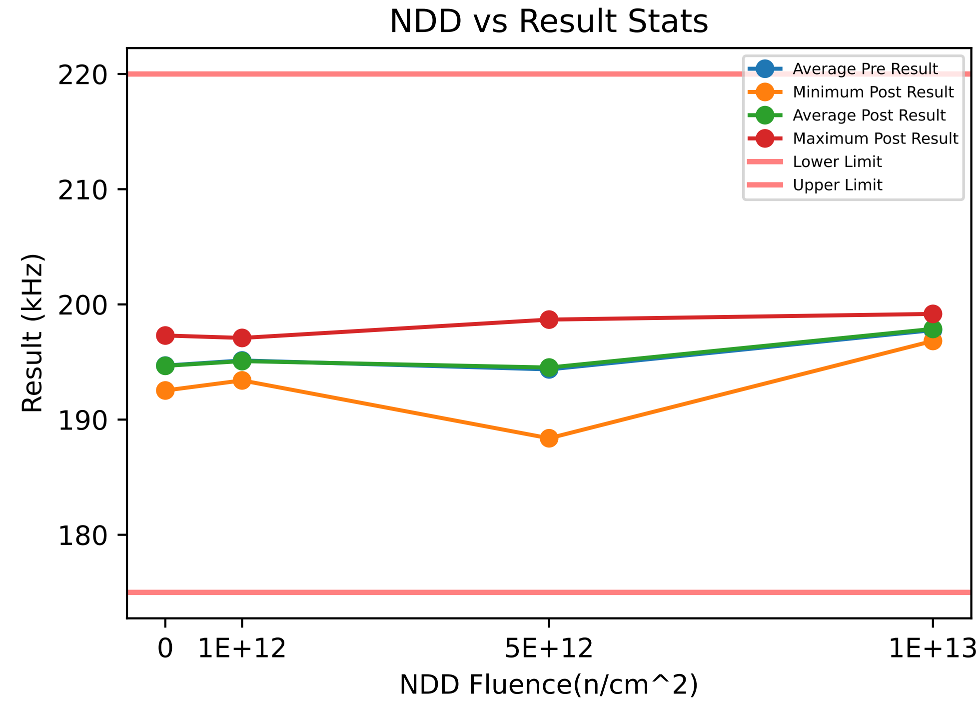
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

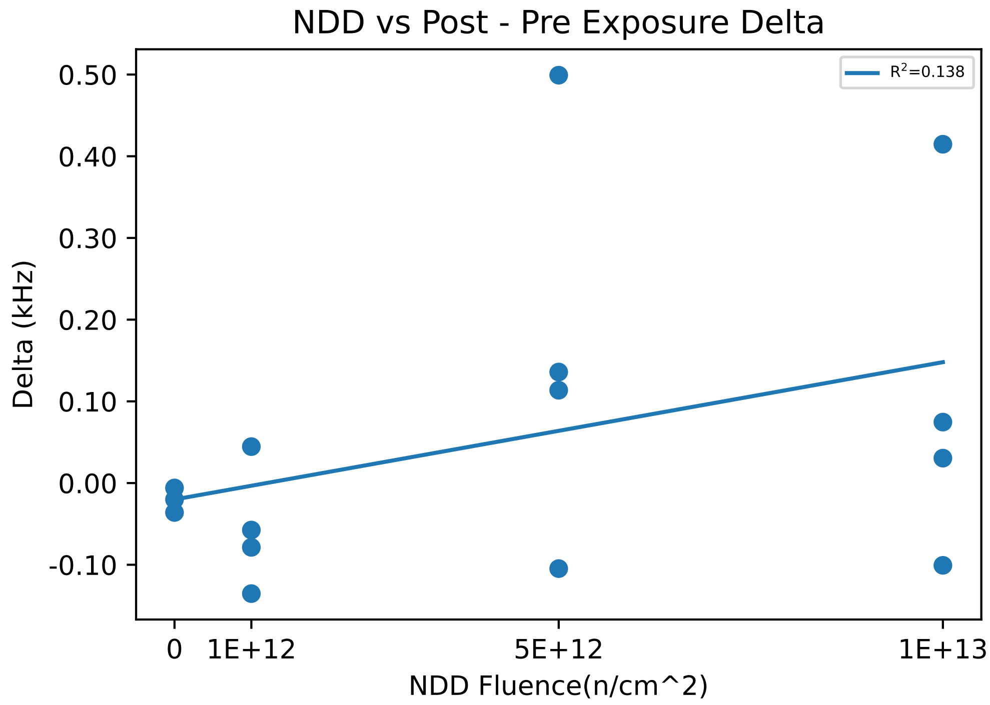
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200.01	199.99	-0.0179
2	1e+12	NDD	200	200	-0.0026
3	1e+12	NDD	200.01	200	-0.0041
4	1e+12	NDD	200	199.99	-0.0116
5	5e+12	NDD	200.01	200	-0.0052
6	5e+12	NDD	200.01	200	-0.0041
7	5e+12	NDD	200.01	200	-0.0156
8	5e+12	NDD	200	200	-0.0086
9	1e+13	NDD	200.01	200	-0.0131
10	1e+13	NDD	200	200	-0.0084
11	1e+13	NDD	200.01	200	-0.0153
12	1e+13	NDD	200.01	200	-0.0109
13	0	CORRELATION	200	200	-0.0082
14	0	CORRELATION	200.01	200	-0.011
15	0	CORRELATION	200.01	200	-0.0117

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200	200.01	200.01	0.0040632	200	200	200	0.0033451	-0.0117	-0.0103	-0.0082	0.001852
1e+12	200	200.01	200.01	0.0023443	199.99	200	200	0.006687	-0.0179	-0.00905	-0.0026	0.007093
5e+12	200	200.01	200.01	0.0027439	200	200	200	0.0034025	-0.0156	-0.008375	-0.0041	0.0051835
1e+13	200	200.01	200.01	0.0041593	200	200	200	0.0031009	-0.0153	-0.011925	-0.0084	0.0029579

Device Test: 20.85 LEVEL|FREQ/RT/14/14/0/1000/5/200kHz//@FSW_EXT_RT_B


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

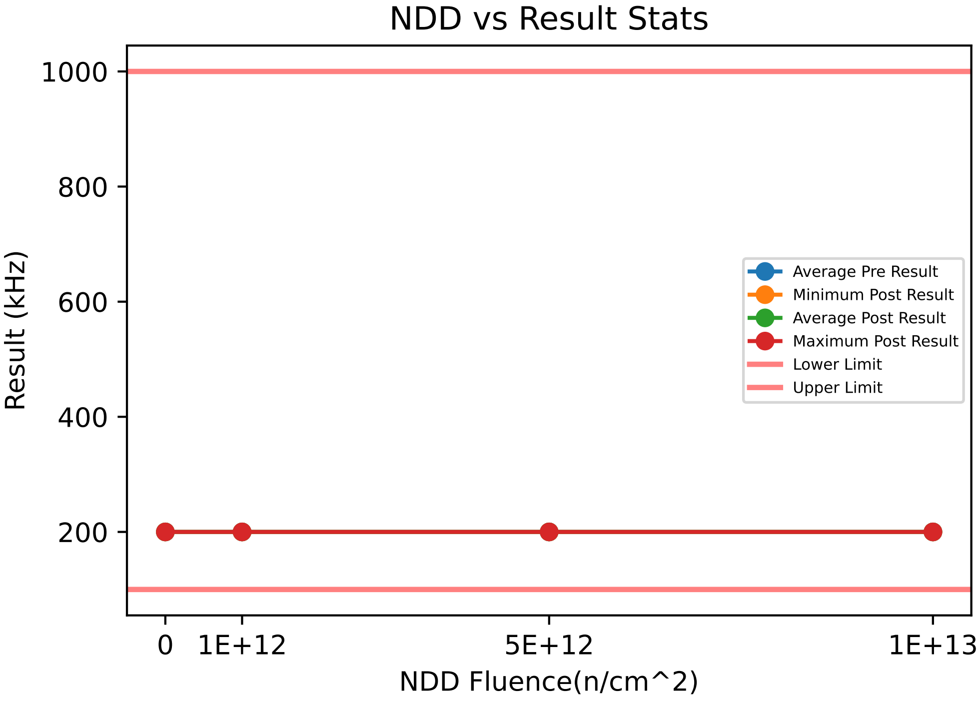
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

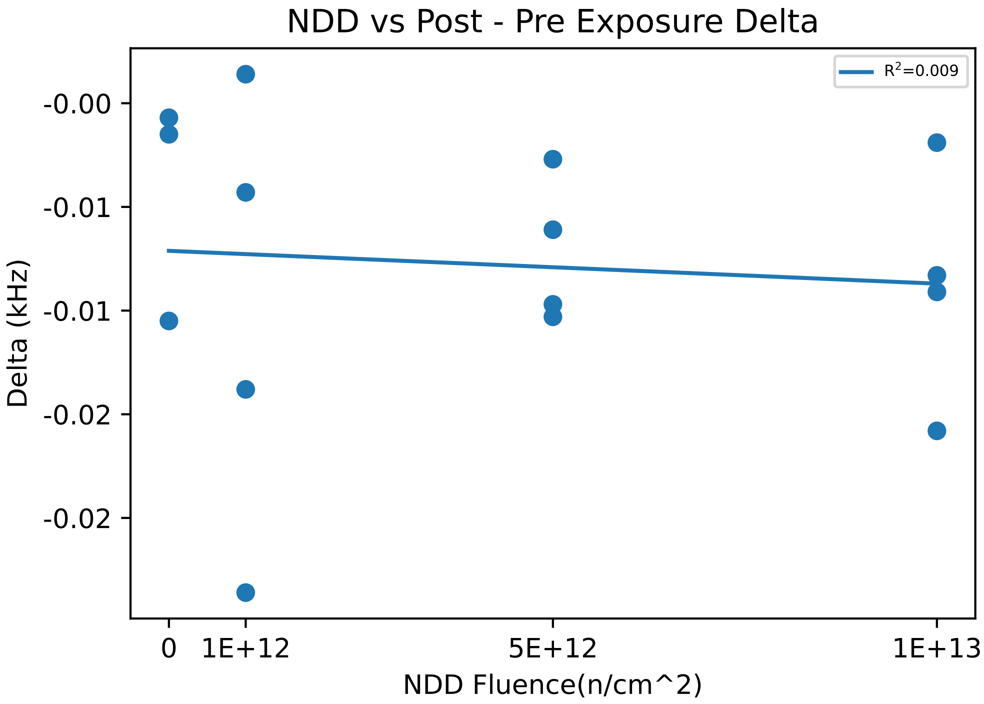
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	197.17	197.09	-0.0787
2	1e+12	NDD	193.46	193.4	-0.0575
3	1e+12	NDD	194.45	194.5	0.0446
4	1e+12	NDD	195.46	195.32	-0.1353
5	5e+12	NDD	188.24	188.38	0.1359
6	5e+12	NDD	192.8	192.92	0.1136
7	5e+12	NDD	197.6	198.1	0.4992
8	5e+12	NDD	198.79	198.68	-0.1047
9	1e+13	NDD	197.41	197.83	0.4147
10	1e+13	NDD	197.58	197.65	0.0746
11	1e+13	NDD	199.27	199.17	-0.1007
12	1e+13	NDD	196.8	196.83	0.0305
13	0	CORRELATION	194.2	194.18	-0.0201
14	0	CORRELATION	197.3	197.3	-0.006
15	0	CORRELATION	192.56	192.53	-0.036

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.56	194.69	197.3	2.4083	192.53	194.67	197.3	2.4229	-0.036	-0.0207	-0.006	0.015009
1e+12	193.46	195.13	197.17	1.5822	193.4	195.08	197.09	1.5548	-0.1353	-0.056725	0.0446	0.075109
5e+12	188.24	194.36	198.79	4.8277	188.38	194.52	198.68	4.8443	-0.1047	0.161	0.4992	0.25023
1e+13	196.8	197.77	199.27	1.0604	196.83	197.87	199.17	0.97199	-0.1007	0.10478	0.4147	0.21962

Device Test: 20.86 LEVEL|FREQ/SYNC/14/14/0/1000/5/200kHz//@FREQ_SYNC_EXT





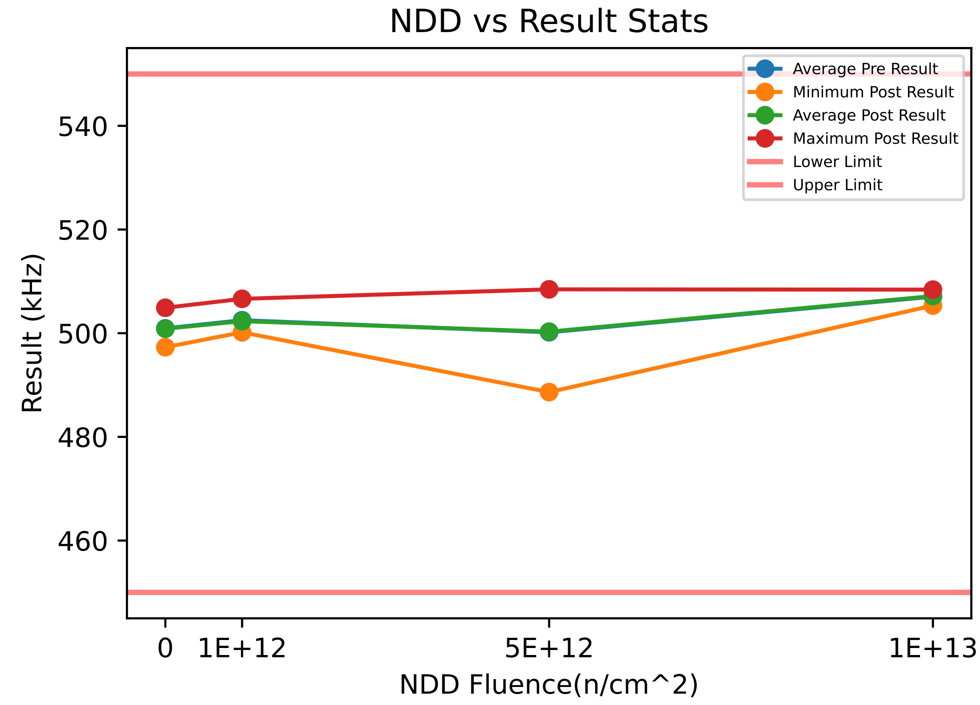
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

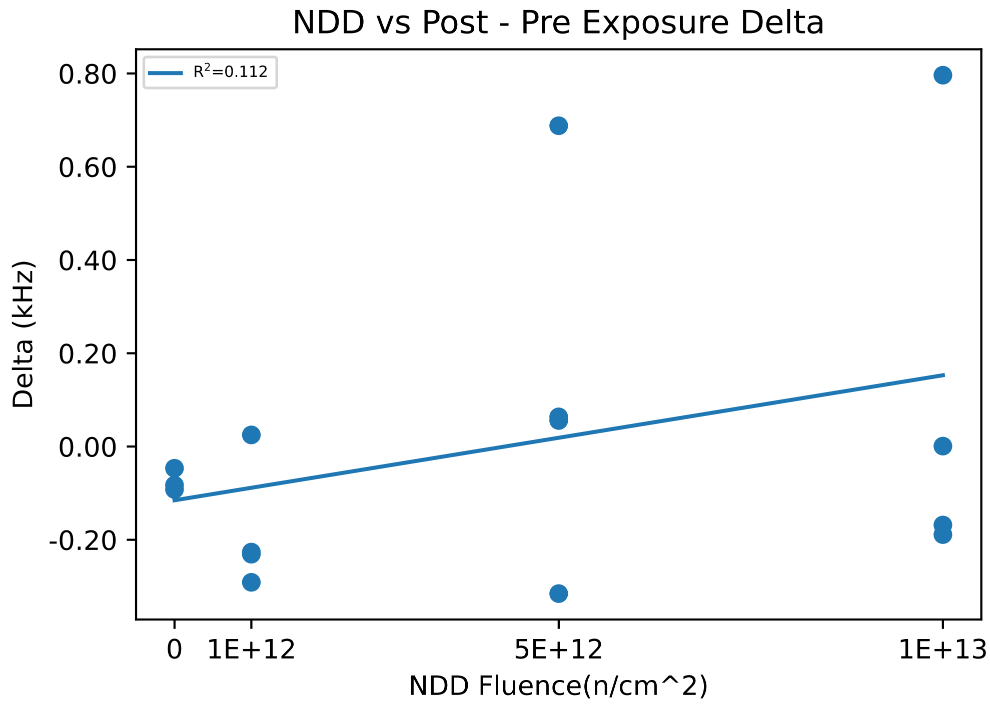
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	200.01	199.99	-0.0188
2	1e+12	NDD	200.01	200	-0.0036
3	1e+12	NDD	200.01	200	-0.0093
4	1e+12	NDD	200	199.98	-0.0286
5	5e+12	NDD	200.01	200	-0.0153
6	5e+12	NDD	200.01	200	-0.0147
7	5e+12	NDD	200	199.99	-0.0077
8	5e+12	NDD	200.01	200	-0.0111
9	1e+13	NDD	200.02	200	-0.0208
10	1e+13	NDD	200	199.99	-0.0141
11	1e+13	NDD	200	200	-0.0069
12	1e+13	NDD	200.01	200	-0.0133
13	0	CORRELATION	200.01	199.99	-0.0155
14	0	CORRELATION	200.01	200	-0.0057
15	0	CORRELATION	200.01	200	-0.0065

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200.01	200.01	200.01	0.0014012	199.99	200	200	0.0064366	-0.0155	-0.0092333	-0.0057	0.0054418
1e+12	200	200.01	200.01	0.0031606	199.98	199.99	200	0.012464	-0.0286	-0.015075	-0.0036	0.010982
5e+12	200	200.01	200.01	0.0060773	199.99	199.99	200	0.0029777	-0.0153	-0.0122	-0.0077	0.003527
1e+13	200	200.01	200.02	0.0060008	199.99	200	200	0.002953	-0.0208	-0.013775	-0.0069	0.0056847

Device Test: 20.87 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/500kHz//@FSW_EXT_RT_C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

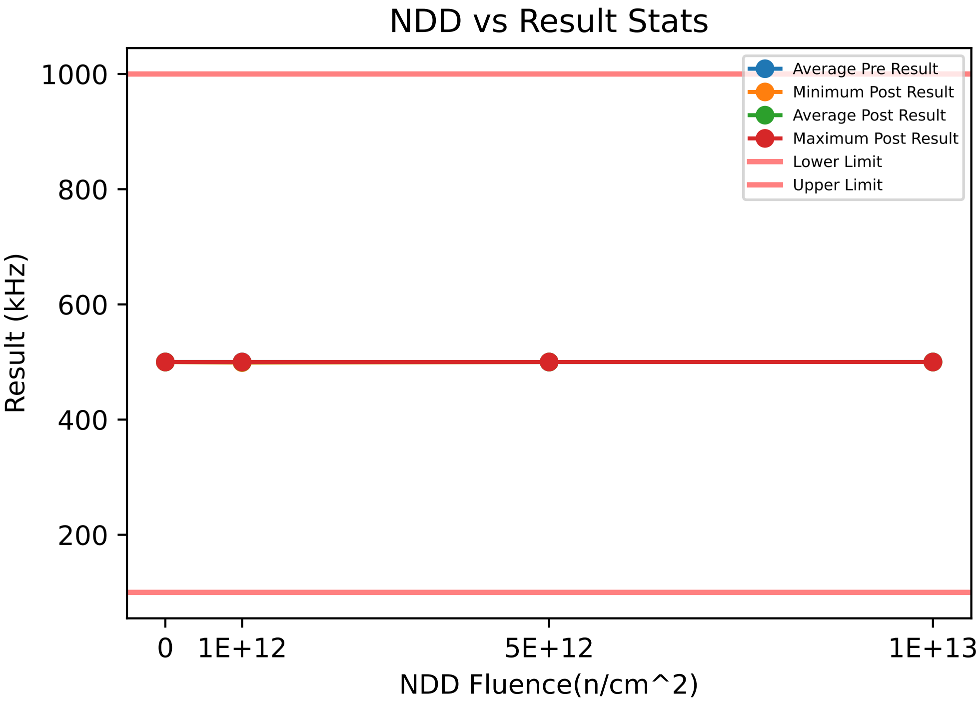
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

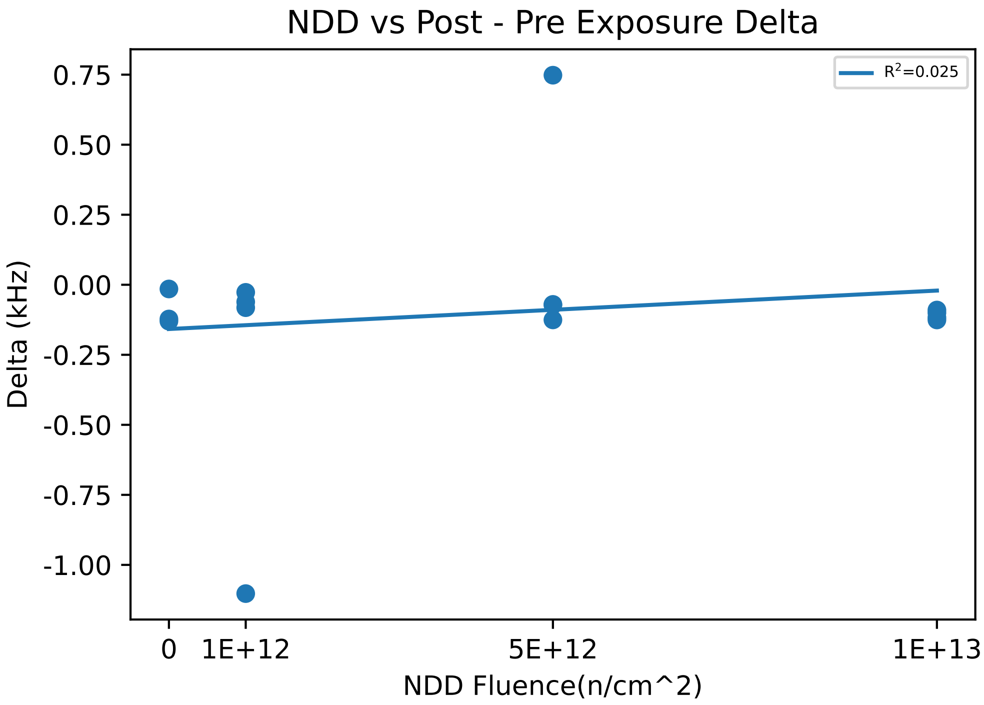
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	506.86	506.63	-0.2264
2	1e+12	NDD	500.4	500.17	-0.2309
3	1e+12	NDD	500.22	500.24	0.0249
4	1e+12	NDD	502.53	502.24	-0.2912
5	5e+12	NDD	488.57	488.64	0.0636
6	5e+12	NDD	498.32	498.38	0.0558
7	5e+12	NDD	505.04	505.72	0.6879
8	5e+12	NDD	508.78	508.46	-0.3154
9	1e+13	NDD	507.01	507.81	0.7963
10	1e+13	NDD	507.1	507.1	0.0009
11	1e+13	NDD	508.59	508.4	-0.1889
12	1e+13	NDD	505.5	505.33	-0.1683
13	0	CORRELATION	500.47	500.38	-0.0829
14	0	CORRELATION	504.95	504.91	-0.0466
15	0	CORRELATION	497.39	497.3	-0.092

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	497.39	500.94	504.95	3.8017	497.3	500.86	504.91	3.8251	-0.092	-0.073833	-0.0466	0.02402
1e+12	500.22	502.5	506.86	3.0871	500.17	502.32	506.63	3.0286	-0.2912	-0.1809	0.0249	0.14034
5e+12	488.57	500.18	508.78	8.8626	488.64	500.3	508.46	8.8644	-0.3154	0.12298	0.6879	0.41607
1e+13	505.5	507.05	508.59	1.2634	505.33	507.16	508.4	1.3316	-0.1889	0.11	0.7963	0.46537

Device Test: 20.88 LEVEL|FREQ/SYNC/4.5/4.5/0/1000/4.5/500kHz//@FREQ_SYNC_EXT





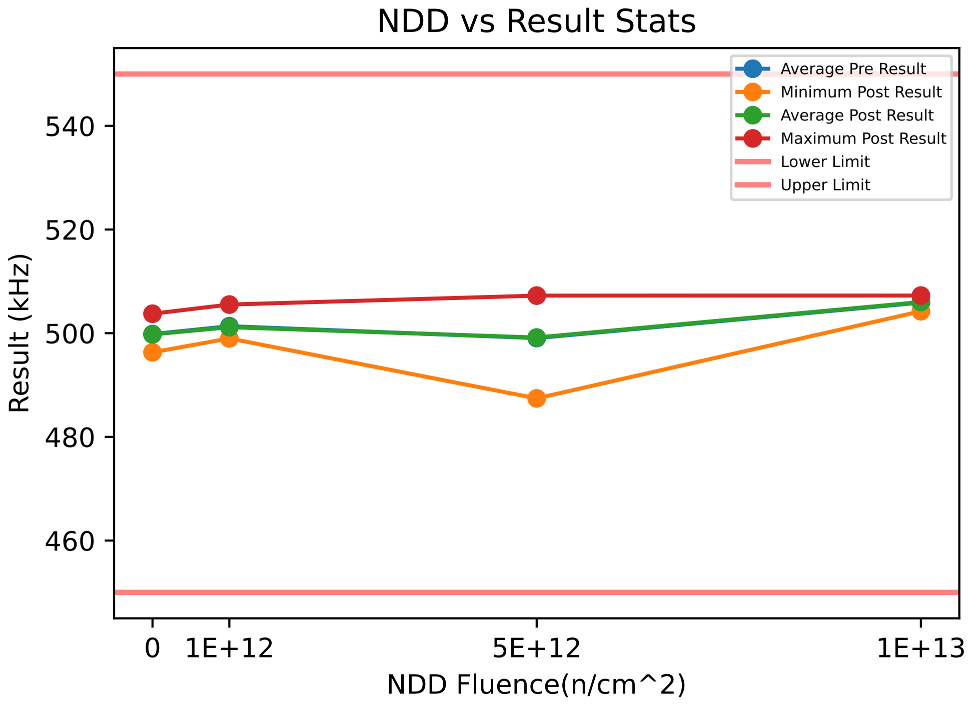
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

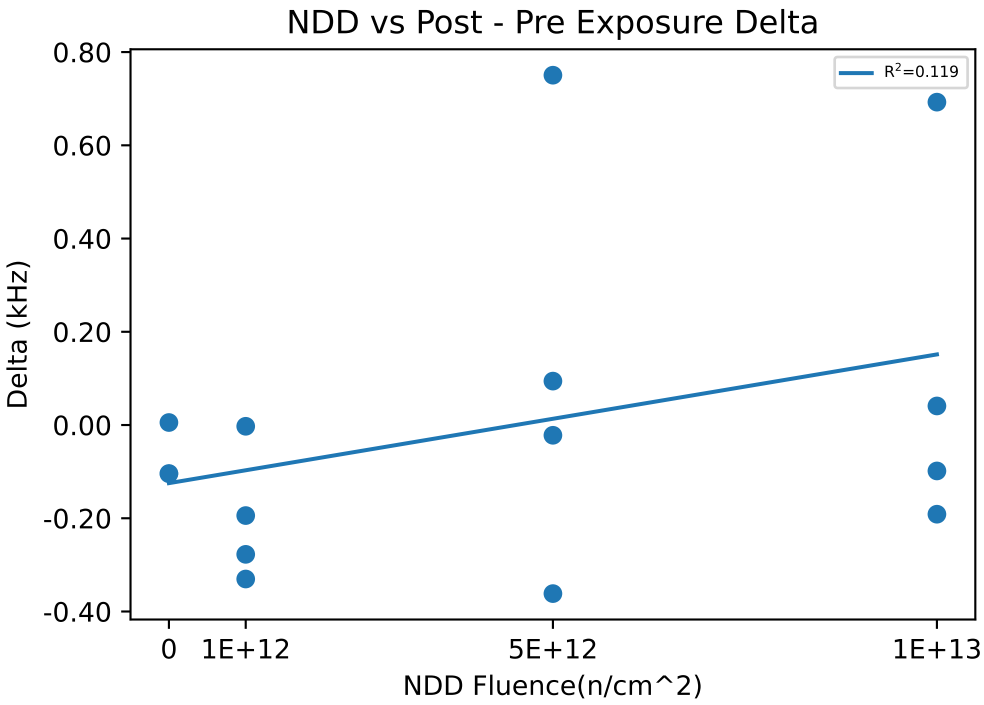
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.01	499.99	-0.0271
2	1e+12	NDD	500.09	500.02	-0.0613
3	1e+12	NDD	500.11	500.02	-0.0818
4	1e+12	NDD	500.02	498.92	-1.1025
5	5e+12	NDD	500.04	499.97	-0.0701
6	5e+12	NDD	500.1	500.02	-0.0721
7	5e+12	NDD	500.07	499.94	-0.1254
8	5e+12	NDD	499.27	500.02	0.7481
9	1e+13	NDD	500.08	499.98	-0.1002
10	1e+13	NDD	500.02	499.93	-0.0902
11	1e+13	NDD	500.1	499.97	-0.1256
12	1e+13	NDD	500.09	499.98	-0.1167
13	0	CORRELATION	500.06	499.93	-0.13
14	0	CORRELATION	500.04	500.03	-0.015
15	0	CORRELATION	500.09	499.97	-0.1222

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.04	500.06	500.09	0.024051	499.93	499.98	500.03	0.046306	-0.13	-0.089067	-0.015	0.064262
1e+12	500.01	500.06	500.11	0.046228	498.92	499.74	500.02	0.54722	-1.1025	-0.31818	-0.0271	0.52337
5e+12	499.27	499.87	500.1	0.39748	499.94	499.99	500.02	0.041107	-0.1254	0.12012	0.7481	0.41943
1e+13	500.02	500.07	500.1	0.035135	499.93	499.97	499.98	0.022518	-0.1256	-0.10817	-0.0902	0.015948

Device Test: 20.89 LEVEL|FREQ/RT/5/5/0/1000/5/500kHz//@FSW_EXT_RT_C





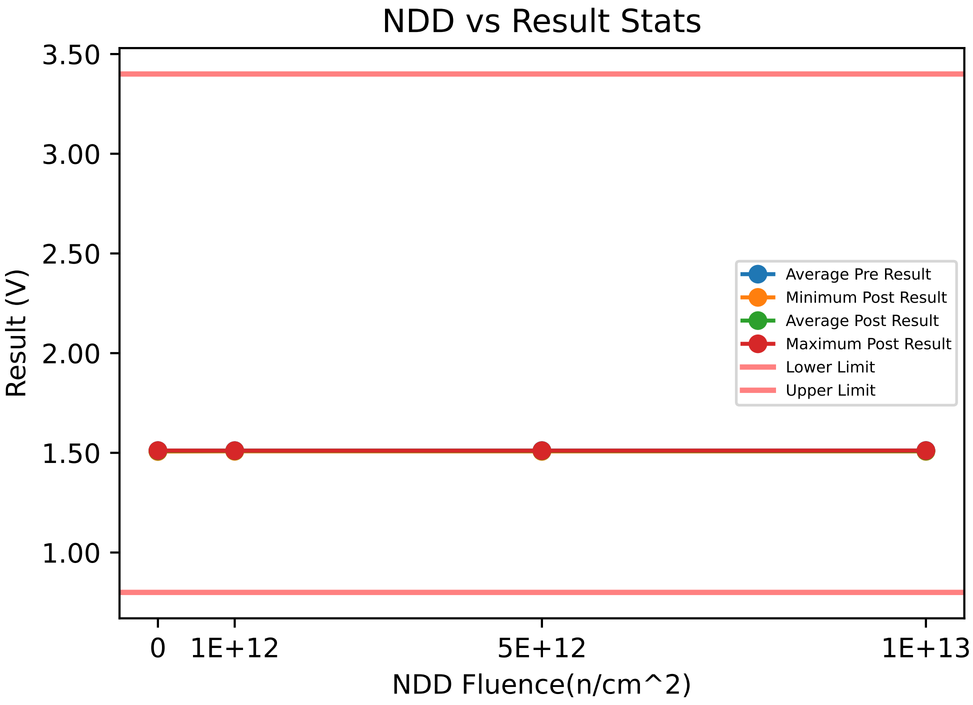
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

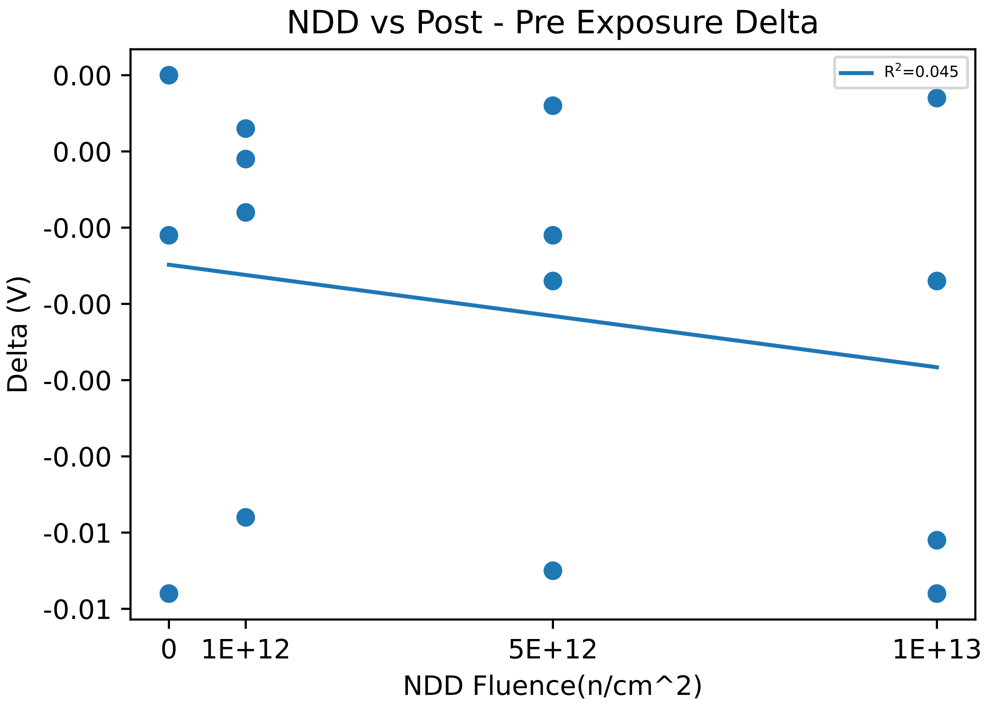
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.81	505.53	-0.2774
2	1e+12	NDD	499.19	498.99	-0.1942
3	1e+12	NDD	499.08	499.08	-0.0027
4	1e+12	NDD	501.34	501.01	-0.3303
5	5e+12	NDD	487.45	487.43	-0.022
6	5e+12	NDD	497.16	497.25	0.0942
7	5e+12	NDD	503.99	504.75	0.7504
8	5e+12	NDD	507.61	507.25	-0.3616
9	1e+13	NDD	505.93	506.62	0.6926
10	1e+13	NDD	506.04	505.94	-0.0985
11	1e+13	NDD	507.45	507.26	-0.1913
12	1e+13	NDD	504.19	504.23	0.0409
13	0	CORRELATION	499.34	499.23	-0.1044
14	0	CORRELATION	503.75	503.76	0.0054
15	0	CORRELATION	496.41	496.31	-0.104

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.41	499.83	503.75	3.6952	496.31	499.77	503.76	3.7533	-0.1044	-0.067667	0.0054	0.063278
1e+12	499.08	501.35	505.81	3.1458	498.99	501.15	505.53	3.0628	-0.3303	-0.20115	-0.0027	0.14367
5e+12	487.45	499.05	507.61	8.8681	487.43	499.17	507.25	8.9062	-0.3616	0.11525	0.7504	0.4655
1e+13	504.19	505.9	507.45	1.3366	504.23	506.01	507.26	1.306	-0.1913	0.11092	0.6926	0.39935

Device Test: 20.9 LEVEL|LOW_LEVEL/SYNC/5.5/5.5/0/0/5.5/500kHz//@SYNC_VIL_TH_LOW_5P5





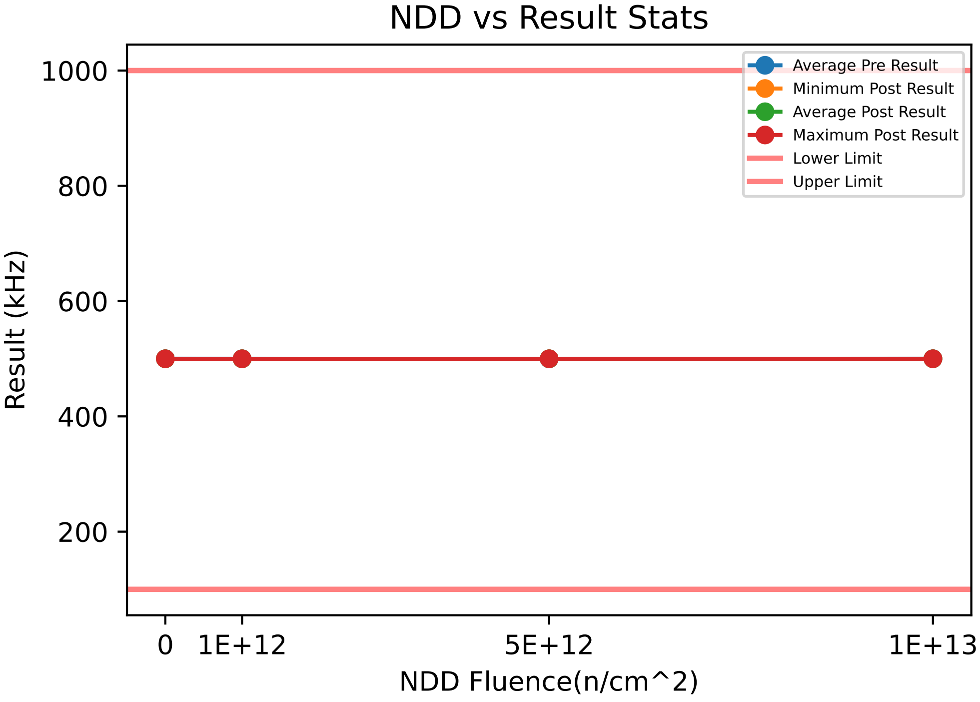
Test Results (Lower Limit = 0.8, Upper Limit = 3.4 (V))

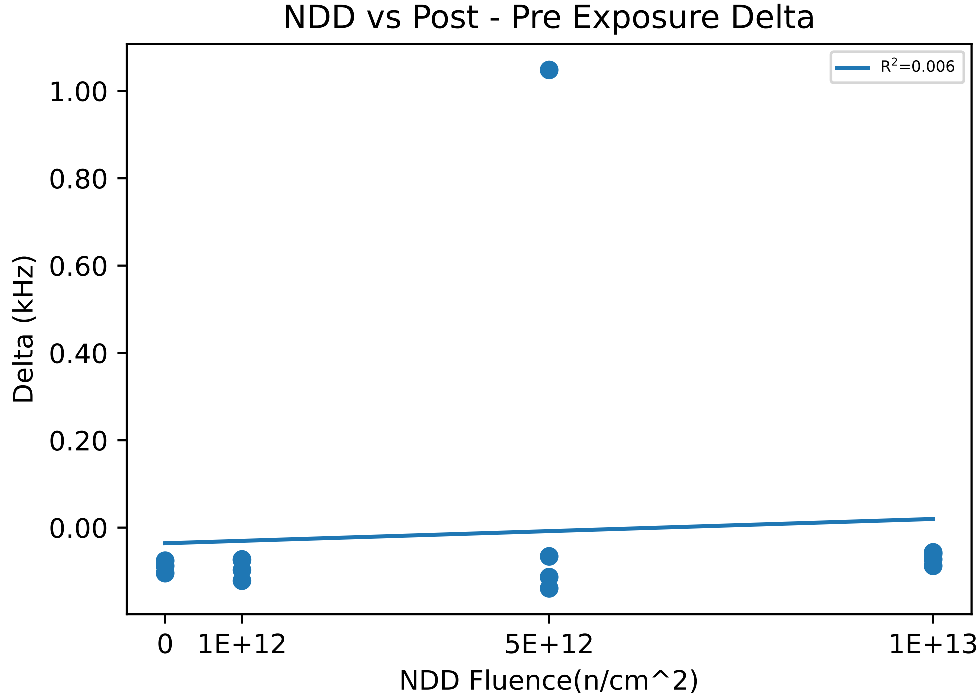
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5111	1.511	-0.0001
2	1e+12	NDD	1.5112	1.5104	-0.0008
3	1e+12	NDD	1.5122	1.5074	-0.0048
4	1e+12	NDD	1.5107	1.511	0.0003
5	5e+12	NDD	1.5118	1.5101	-0.0017
6	5e+12	NDD	1.5126	1.5071	-0.0055
7	5e+12	NDD	1.5104	1.511	0.0006
8	5e+12	NDD	1.5115	1.5104	-0.0011
9	1e+13	NDD	1.5122	1.5071	-0.0051
10	1e+13	NDD	1.5107	1.5114	0.0007
11	1e+13	NDD	1.5118	1.5101	-0.0017
12	1e+13	NDD	1.5129	1.5071	-0.0058
13	0	CORRELATION	1.5104	1.5114	0.001
14	0	CORRELATION	1.5115	1.5104	-0.0011
15	0	CORRELATION	1.5122	1.5064	-0.0058

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5104	1.5114	1.5122	0.00090738	1.5064	1.5094	1.5114	0.0026458	-0.0058	-0.0019667	0.001	0.0034819
1e+12	1.5107	1.5113	1.5122	0.0006377	1.5074	1.5099	1.511	0.0017234	-0.0048	-0.00135	0.0003	0.0023445
5e+12	1.5104	1.5116	1.5126	0.00091059	1.5071	1.5096	1.511	0.0017407	-0.0055	-0.001925	0.0006	0.0025747
1e+13	1.5107	1.5119	1.5129	0.00092014	1.5071	1.5089	1.5114	0.0021731	-0.0058	-0.002975	0.0007	0.0030347

Device Test: 20.90 LEVEL|FREQ/SYNC/5/5/0/1000/5/500kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

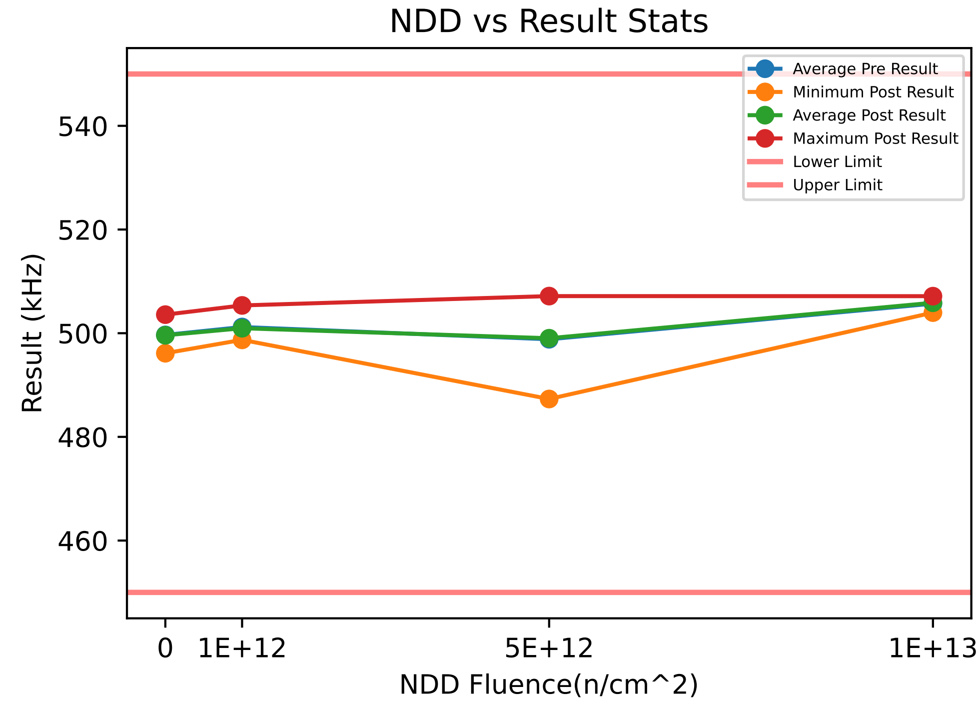
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

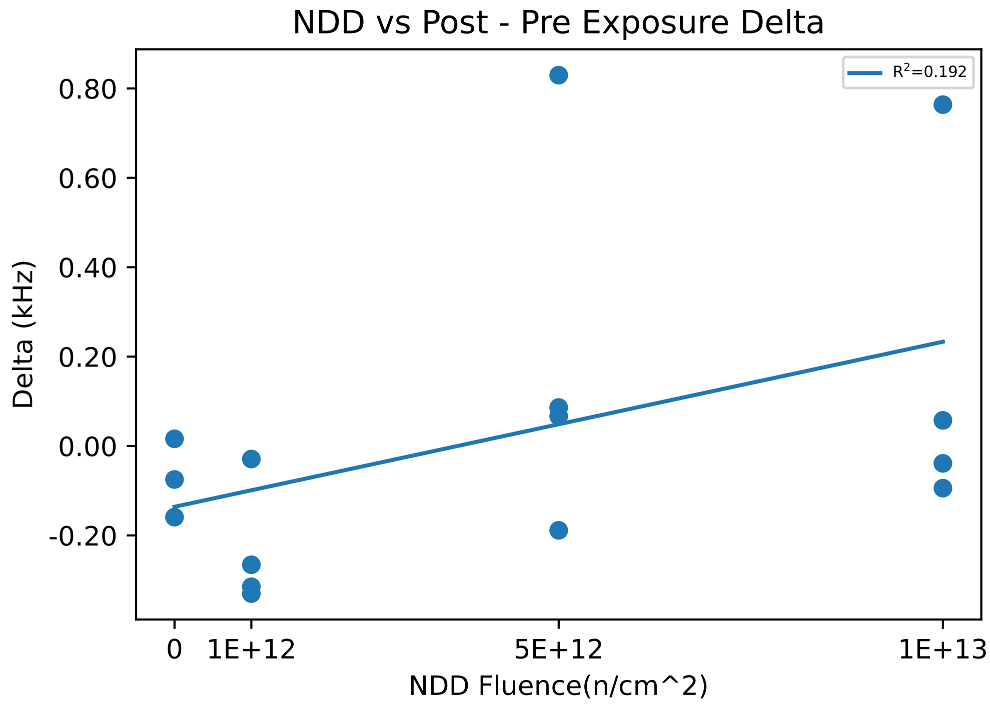
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.01	499.94	-0.0729
2	1e+12	NDD	500.07	499.97	-0.0972
3	1e+12	NDD	500.05	499.98	-0.0744
4	1e+12	NDD	500.06	499.94	-0.1216
5	5e+12	NDD	500.08	500.02	-0.0659
6	5e+12	NDD	500.09	499.98	-0.1133
7	5e+12	NDD	500.08	499.94	-0.1391
8	5e+12	NDD	498.92	499.97	1.0481
9	1e+13	NDD	500.08	500.02	-0.0604
10	1e+13	NDD	500.03	499.94	-0.0876
11	1e+13	NDD	500.08	500.02	-0.0567
12	1e+13	NDD	500.09	500.02	-0.0727
13	0	CORRELATION	500.05	499.98	-0.0758
14	0	CORRELATION	500.07	499.97	-0.1043
15	0	CORRELATION	500.1	500.01	-0.0878

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.05	500.08	500.1	0.023401	499.97	499.99	500.01	0.023526	-0.1043	-0.0893	-0.0758	0.014309
1e+12	500.01	500.05	500.07	0.023877	499.94	499.96	499.98	0.020068	-0.1216	-0.091525	-0.0729	0.022926
5e+12	498.92	499.79	500.09	0.58208	499.94	499.98	500.02	0.031681	-0.1391	0.18245	1.0481	0.5779
1e+13	500.03	500.07	500.09	0.030031	499.94	500	500.02	0.041636	-0.0876	-0.06935	-0.0567	0.013957

Device Test: 20.91 LEVEL|FREQ/RT/12/12/0/1000/5/500kHz//@FSW_EXT_RT_C





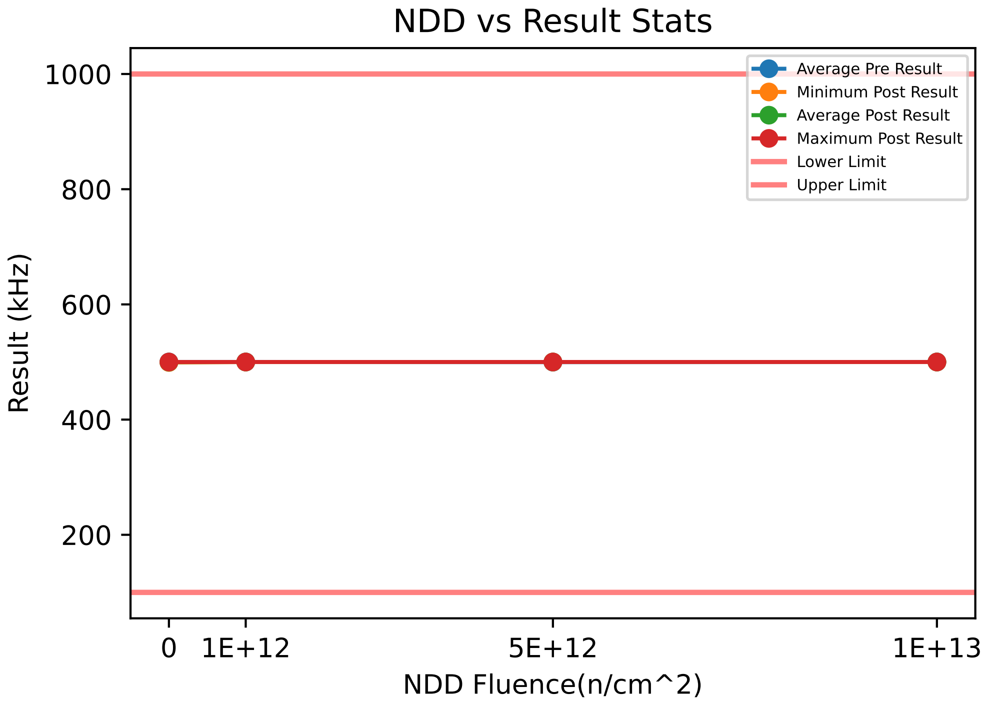
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

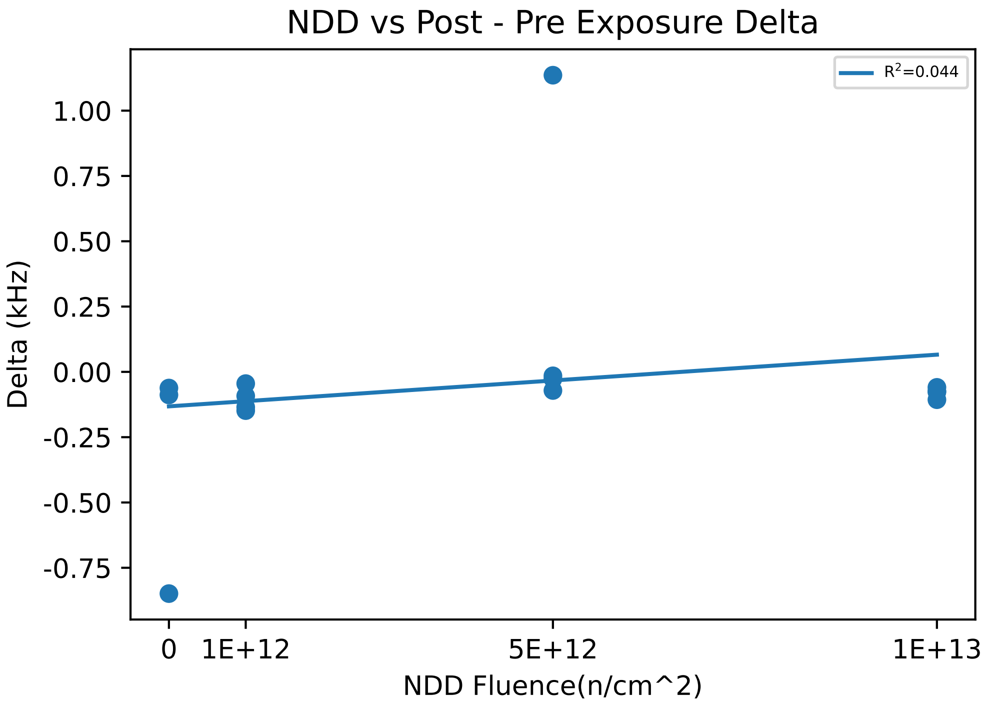
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.67	505.36	-0.3149
2	1e+12	NDD	498.98	498.72	-0.2657
3	1e+12	NDD	498.94	498.91	-0.0291
4	1e+12	NDD	501.18	500.85	-0.3302
5	5e+12	NDD	487.22	487.31	0.0862
6	5e+12	NDD	496.94	497.01	0.0668
7	5e+12	NDD	503.81	504.64	0.8296
8	5e+12	NDD	507.35	507.16	-0.1887
9	1e+13	NDD	505.74	506.51	0.7637
10	1e+13	NDD	505.8	505.86	0.0574
11	1e+13	NDD	507.24	507.14	-0.0943
12	1e+13	NDD	504.01	503.97	-0.0388
13	0	CORRELATION	499.14	499.07	-0.0749
14	0	CORRELATION	503.56	503.58	0.0161
15	0	CORRELATION	496.29	496.13	-0.1592

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.29	499.67	503.56	3.6635	496.13	499.59	503.58	3.7507	-0.1592	-0.072667	0.0161	0.087671
1e+12	498.94	501.19	505.67	3.1642	498.72	500.96	505.36	3.087	-0.3302	-0.23498	-0.0291	0.13998
5e+12	487.22	498.83	507.35	8.8625	487.31	499.03	507.16	8.9258	-0.1887	0.19848	0.8296	0.439
1e+13	504.01	505.7	507.24	1.3203	503.97	505.87	507.14	1.3696	-0.0943	0.172	0.7637	0.39941

Device Test: 20.92 LEVEL|FREQ/SYNC/12/12/0/1000/5/500kHz//@FREQ_SYNC_EXT





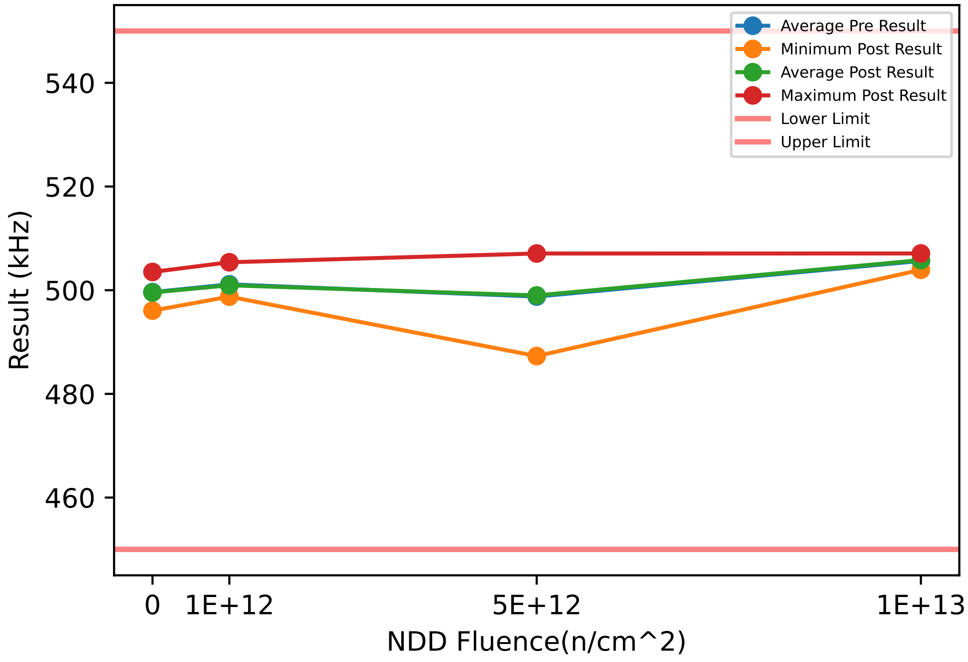
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

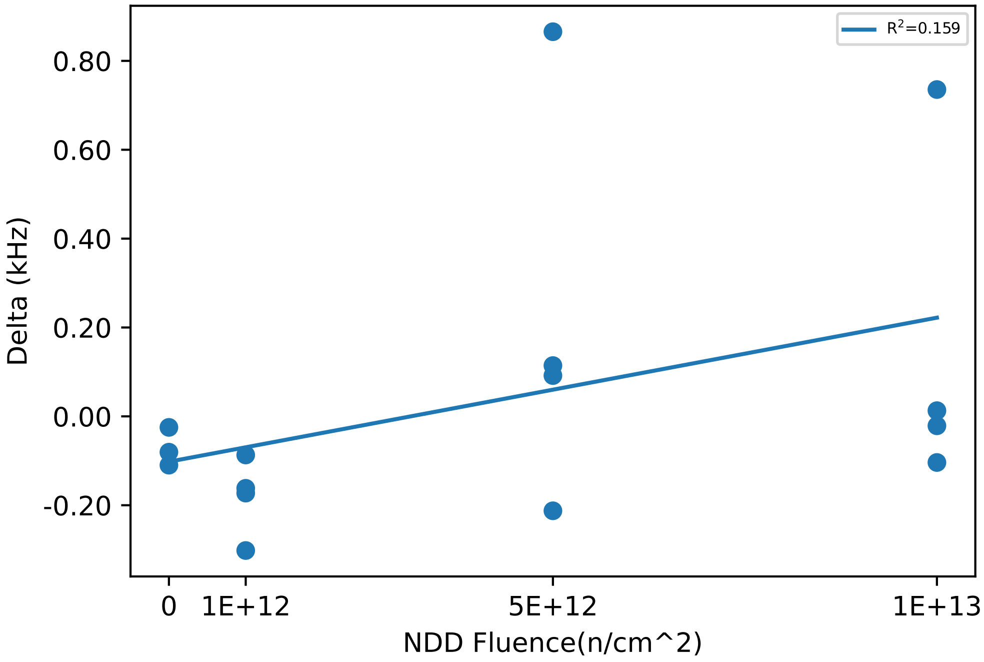
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.09	499.94	-0.1483
2	1e+12	NDD	500.05	500.01	-0.0449
3	1e+12	NDD	500.12	499.98	-0.1352
4	1e+12	NDD	500.02	499.93	-0.0922
5	5e+12	NDD	500.03	500.01	-0.0151
6	5e+12	NDD	500.05	499.98	-0.0713
7	5e+12	NDD	498.83	499.97	1.1357
8	5e+12	NDD	500.03	500	-0.0269
9	1e+13	NDD	500.04	499.98	-0.0593
10	1e+13	NDD	500.01	499.94	-0.077
11	1e+13	NDD	500.08	500.01	-0.074
12	1e+13	NDD	500.09	499.98	-0.1065
13	0	CORRELATION	500.06	499.97	-0.0882
14	0	CORRELATION	500.07	500.01	-0.0619
15	0	CORRELATION	500.05	499.2	-0.8488

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.05	500.06	500.07	0.010767	499.2	499.73	500.01	0.45669	-0.8488	-0.33297	-0.0619	0.44692
1e+12	500.02	500.07	500.12	0.039507	499.93	499.96	500.01	0.035178	-0.1483	-0.10515	-0.0449	0.046771
5e+12	498.83	499.73	500.05	0.60172	499.97	499.99	500.01	0.022213	-0.0713	0.2556	1.1357	0.58723
1e+13	500.01	500.06	500.09	0.03632	499.94	499.98	500.01	0.029871	-0.1065	-0.0792	-0.0593	0.019775

Device Test: 20.93 LEVEL|FREQ/RT/14/14/0/1000/5/500kHz//@FSW_EXT_RT_C


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

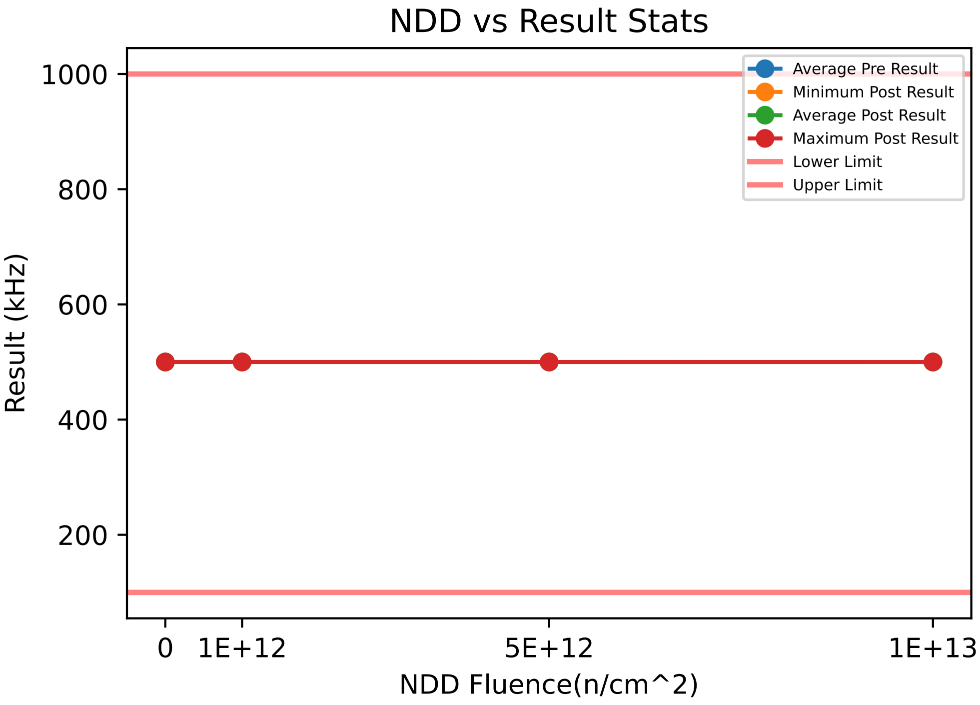
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

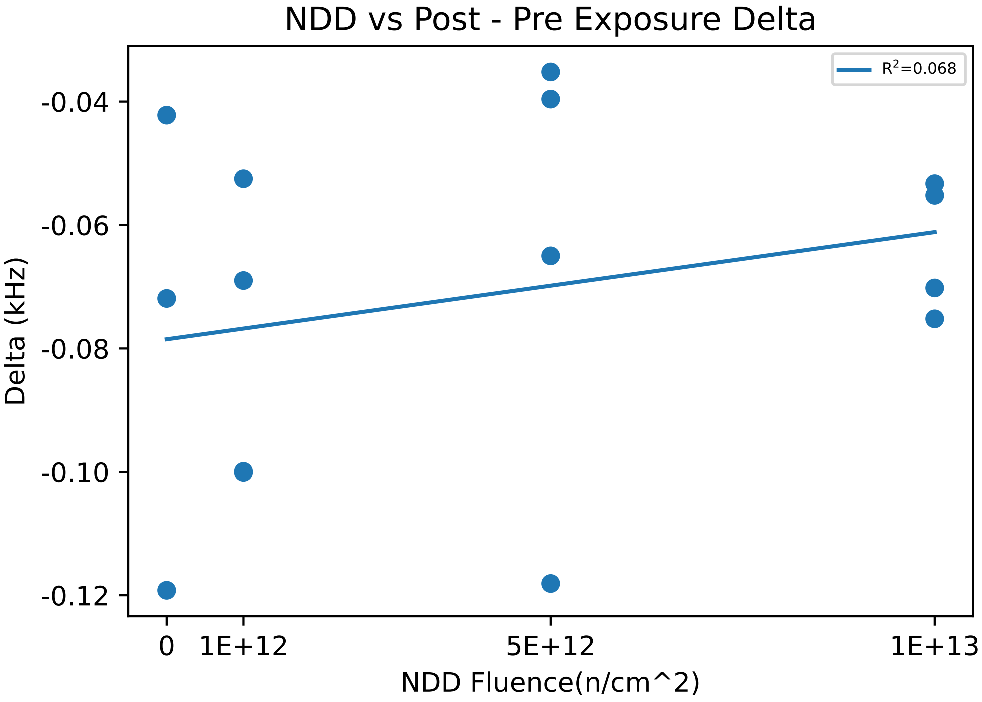
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	505.55	505.39	-0.1619
2	1e+12	NDD	498.93	498.76	-0.1727
3	1e+12	NDD	498.93	498.85	-0.0869
4	1e+12	NDD	501.09	500.79	-0.3019
5	5e+12	NDD	487.18	487.29	0.1143
6	5e+12	NDD	496.9	496.99	0.0918
7	5e+12	NDD	503.72	504.59	0.8656
8	5e+12	NDD	507.29	507.08	-0.2125
9	1e+13	NDD	505.69	506.43	0.7355
10	1e+13	NDD	505.78	505.76	-0.0212
11	1e+13	NDD	507.19	507.09	-0.1038
12	1e+13	NDD	503.93	503.94	0.0128
13	0	CORRELATION	499.17	499.09	-0.0806
14	0	CORRELATION	503.54	503.52	-0.0248
15	0	CORRELATION	496.17	496.06	-0.1098

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.17	499.63	503.54	3.71	496.06	499.56	503.52	3.7531	-0.1098	-0.071733	-0.0248	0.043188
1e+12	498.93	501.13	505.55	3.1211	498.76	500.95	505.39	3.1079	-0.3019	-0.18085	-0.0869	0.089266
5e+12	487.18	498.77	507.29	8.8501	487.29	498.99	507.08	8.8986	-0.2125	0.2148	0.8656	0.45875
1e+13	503.93	505.65	507.19	1.336	503.94	505.8	507.09	1.3548	-0.1038	0.15583	0.7355	0.38954

Device Test: 20.94 LEVEL|FREQ/SYNC/14/14/0/1000/5/500kHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

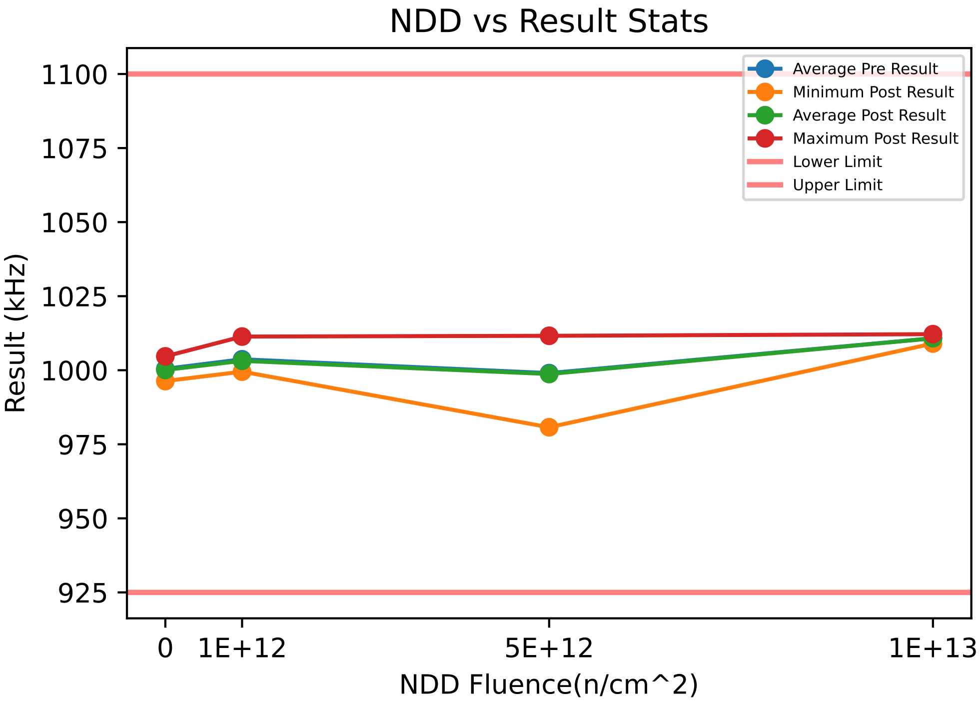
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

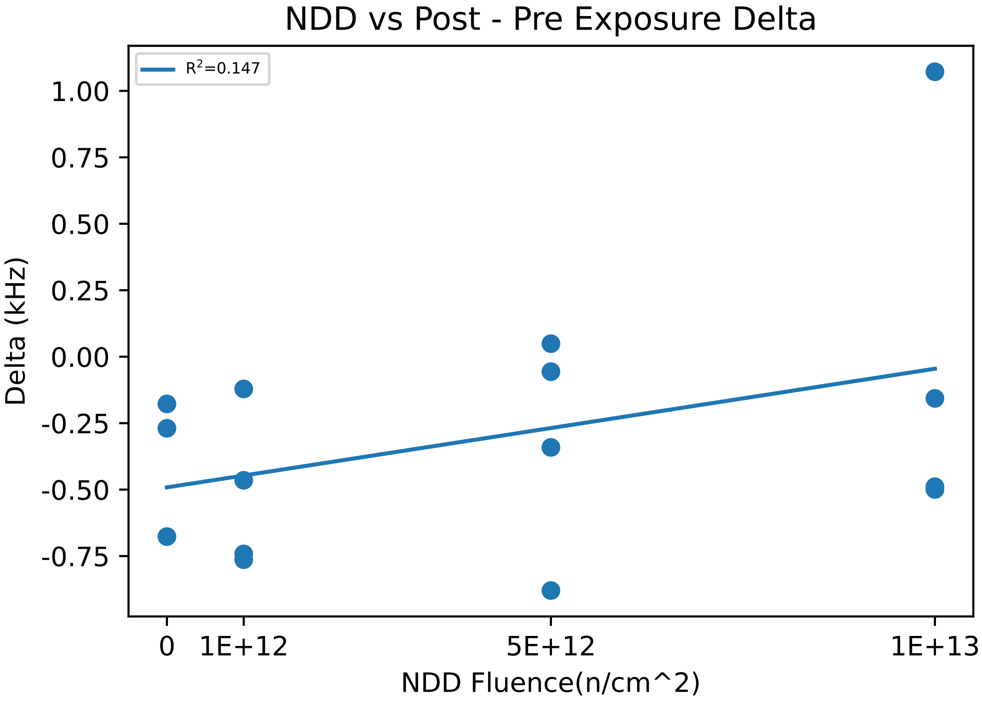
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	500.04	499.94	-0.0999
2	1e+12	NDD	500.06	500.01	-0.0525
3	1e+12	NDD	500.07	499.97	-0.1001
4	1e+12	NDD	500.04	499.97	-0.069
5	5e+12	NDD	500.02	499.98	-0.0396
6	5e+12	NDD	500.04	499.97	-0.065
7	5e+12	NDD	500.05	499.94	-0.1181
8	5e+12	NDD	500.04	500	-0.0352
9	1e+13	NDD	500.05	499.98	-0.0752
10	1e+13	NDD	500.03	499.98	-0.0533
11	1e+13	NDD	500.03	499.97	-0.0552
12	1e+13	NDD	500.04	499.97	-0.0702
13	0	CORRELATION	500.05	499.93	-0.1192
14	0	CORRELATION	500.04	500	-0.0422
15	0	CORRELATION	500.08	500.01	-0.0719

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.04	500.06	500.08	0.021457	499.93	499.98	500.01	0.04228	-0.1192	-0.077767	-0.0422	0.038834
1e+12	500.04	500.05	500.07	0.016898	499.94	499.97	500.01	0.029689	-0.1001	-0.080375	-0.0525	0.023641
5e+12	500.02	500.04	500.05	0.013743	499.94	499.97	500	0.027421	-0.1181	-0.064475	-0.0352	0.038086
1e+13	500.03	500.04	500.05	0.0119	499.97	499.97	499.98	0.0027068	-0.0752	-0.063475	-0.0533	0.010874

Device Test: 20.95 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/1MHz//@FSW_EXT_RT_D


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

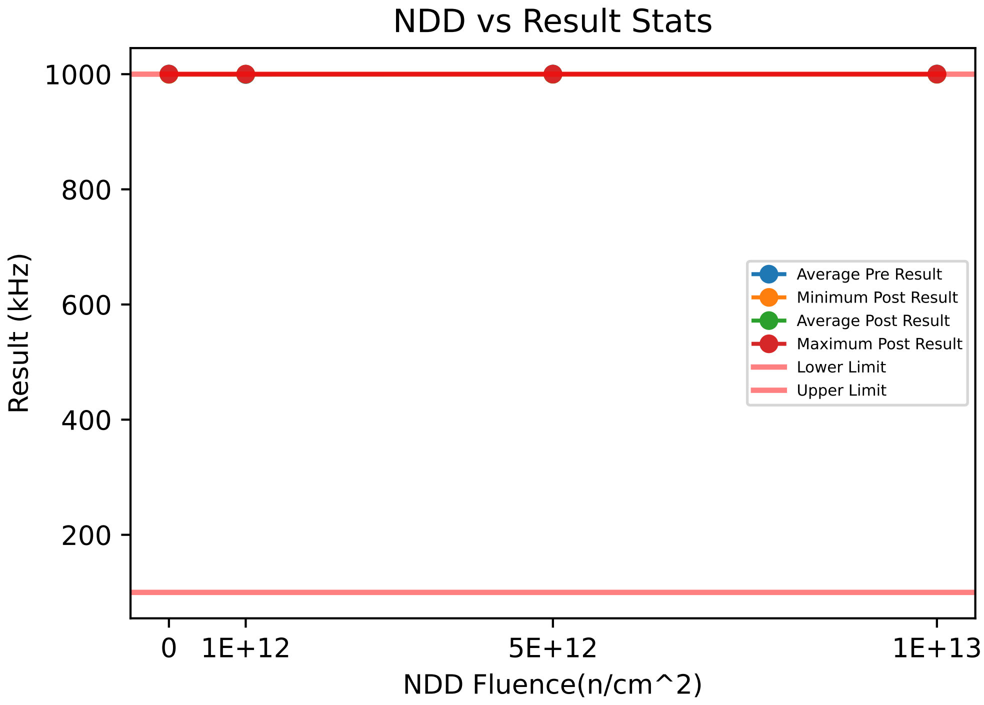
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

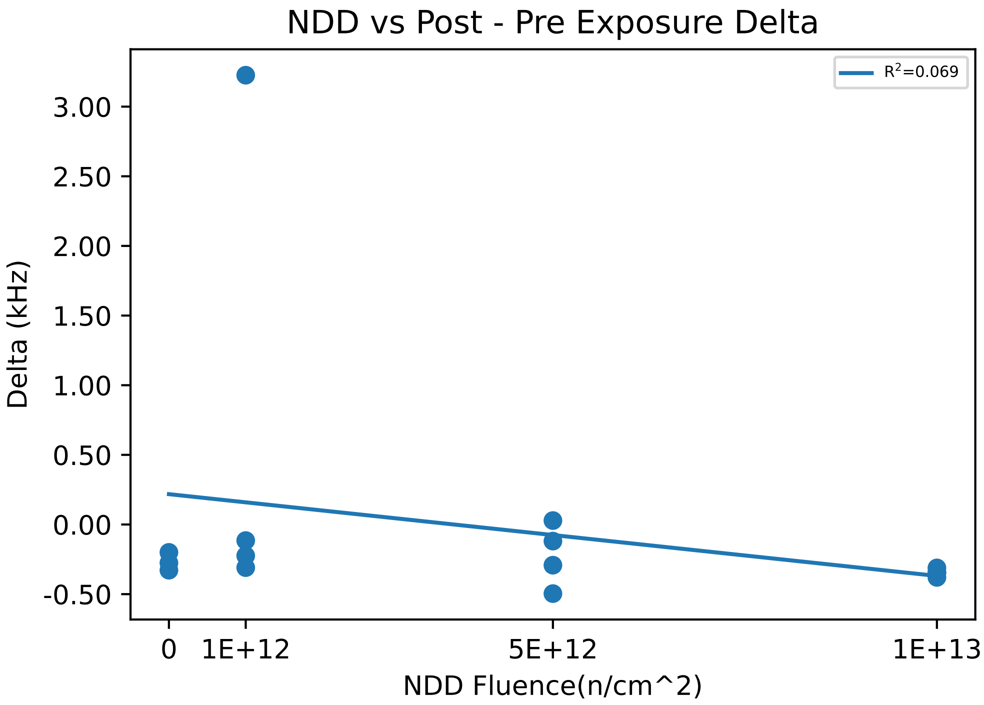
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1012.1	1011.4	-0.7637
2	1e+12	NDD	999.98	999.52	-0.465
3	1e+12	NDD	999.73	999.61	-0.1214
4	1e+12	NDD	1002.9	1002.2	-0.7418
5	5e+12	NDD	981.09	980.75	-0.3412
6	5e+12	NDD	998.16	998.21	0.0489
7	5e+12	NDD	1004.4	1004.3	-0.0563
8	5e+12	NDD	1012.5	1011.6	-0.8796
9	1e+13	NDD	1011.1	1012.2	1.0719
10	1e+13	NDD	1011.7	1011.3	-0.4891
11	1e+13	NDD	1011.2	1010.7	-0.4995
12	1e+13	NDD	1009.2	1009	-0.1569
13	0	CORRELATION	999.93	999.25	-0.6768
14	0	CORRELATION	1004.9	1004.7	-0.2693
15	0	CORRELATION	996.52	996.34	-0.1776

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	996.52	1000.5	1004.9	4.2399	996.34	1000.1	1004.7	4.2313	-0.6768	-0.37457	-0.1776	0.26573
1e+12	999.73	1003.7	1012.1	5.8081	999.52	1003.2	1011.4	5.6013	-0.7637	-0.52297	-0.1214	0.30025
5e+12	981.09	999.03	1012.5	13.324	980.75	998.72	1011.6	13.177	-0.8796	-0.30705	0.0489	0.41575
1e+13	1009.2	1010.8	1011.7	1.1217	1009	1010.8	1012.2	1.3294	-0.4995	-0.0184	1.0719	0.74408

Device Test: 20.96 LEVEL|FREQ/SYNC/4.5/4.5/0/1000/4.5/1MHz//@FREQ_SYNC_EXT


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

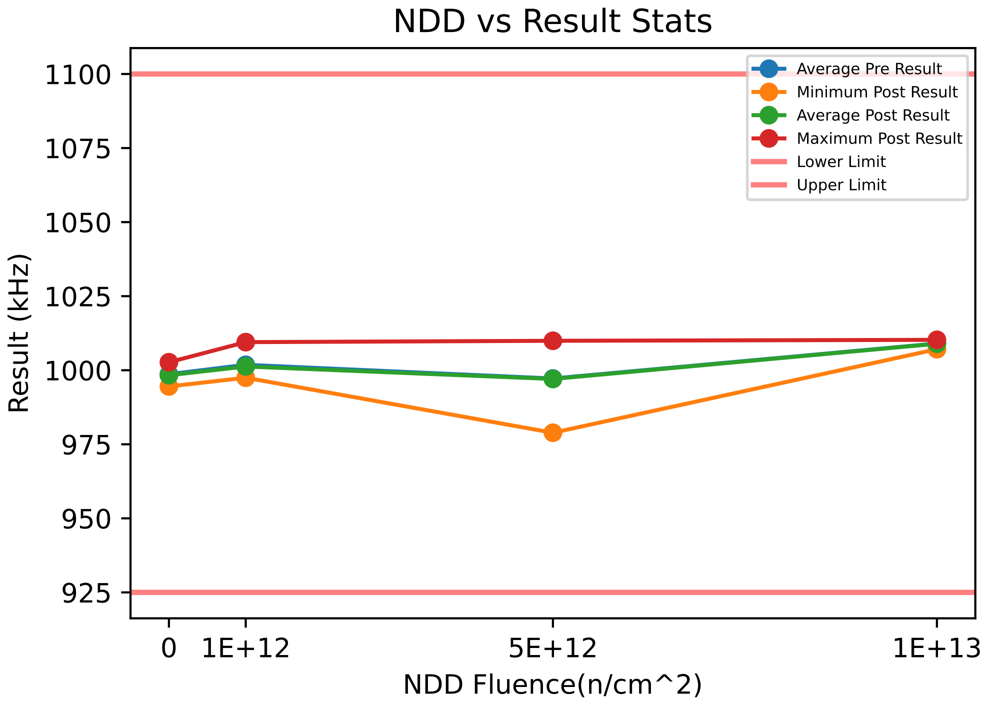
Test Results (Lower Limit = 100.0, Upper Limit = 1000.0 (kHz))

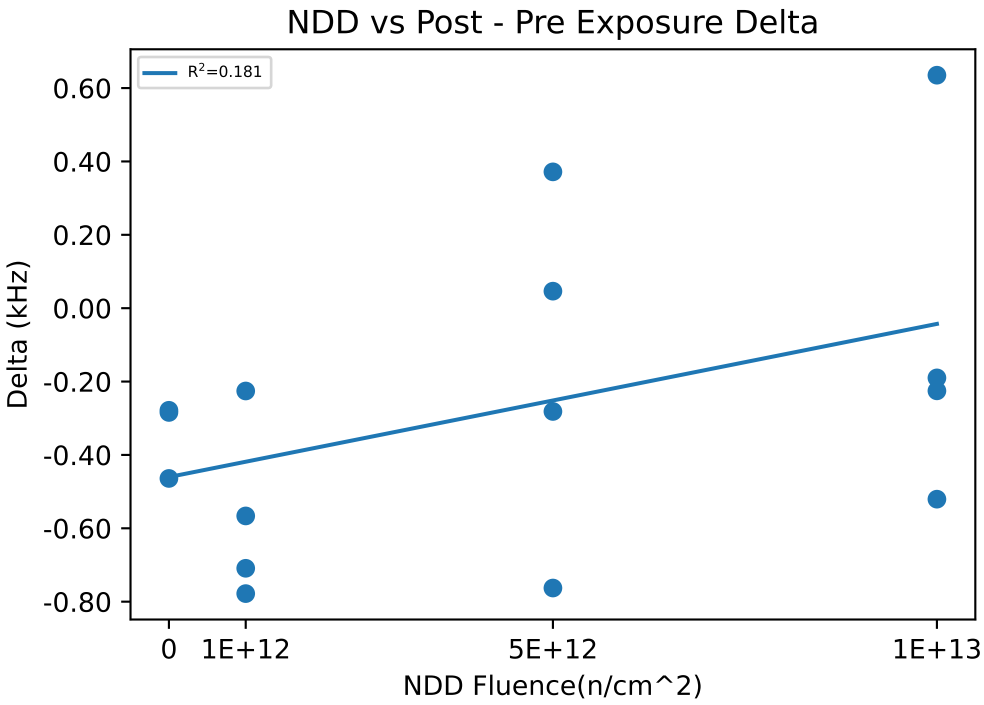
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000	999.78	-0.2243
2	1e+12	NDD	996.85	1000.1	3.2257
3	1e+12	NDD	1000.3	1000.1	-0.1153
4	1e+12	NDD	1000.2	999.9	-0.3096
5	5e+12	NDD	1000.2	999.89	-0.2922
6	5e+12	NDD	1000.4	999.92	-0.4961
7	5e+12	NDD	1000.1	999.95	-0.1192
8	5e+12	NDD	1000.1	1000.1	0.0283
9	1e+13	NDD	1000.5	1000.1	-0.3436
10	1e+13	NDD	1000.2	999.9	-0.3118
11	1e+13	NDD	1000.2	999.88	-0.3471
12	1e+13	NDD	1000.3	999.92	-0.3797
13	0	CORRELATION	1000	999.72	-0.3282
14	0	CORRELATION	1000.2	1000	-0.2002
15	0	CORRELATION	1000.4	1000.1	-0.2758

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000	1000.2	1000.4	0.17705	999.72	999.96	1000.1	0.21461	-0.3282	-0.26807	-0.2002	0.064349
1e+12	996.85	999.33	1000.3	1.6553	999.78	999.98	1000.1	0.16212	-0.3096	0.64413	3.2257	1.7229
5e+12	1000.1	1000.2	1000.4	0.15583	999.89	999.97	1000.1	0.11189	-0.4961	-0.2198	0.0283	0.22602
1e+13	1000.2	1000.3	1000.5	0.11145	999.88	999.95	1000.1	0.10734	-0.3797	-0.34555	-0.3118	0.027758

Device Test: 20.97 LEVEL|FREQ/RT/5/5/0/1000/5/1MHz//@FSW_EXT_RT_D





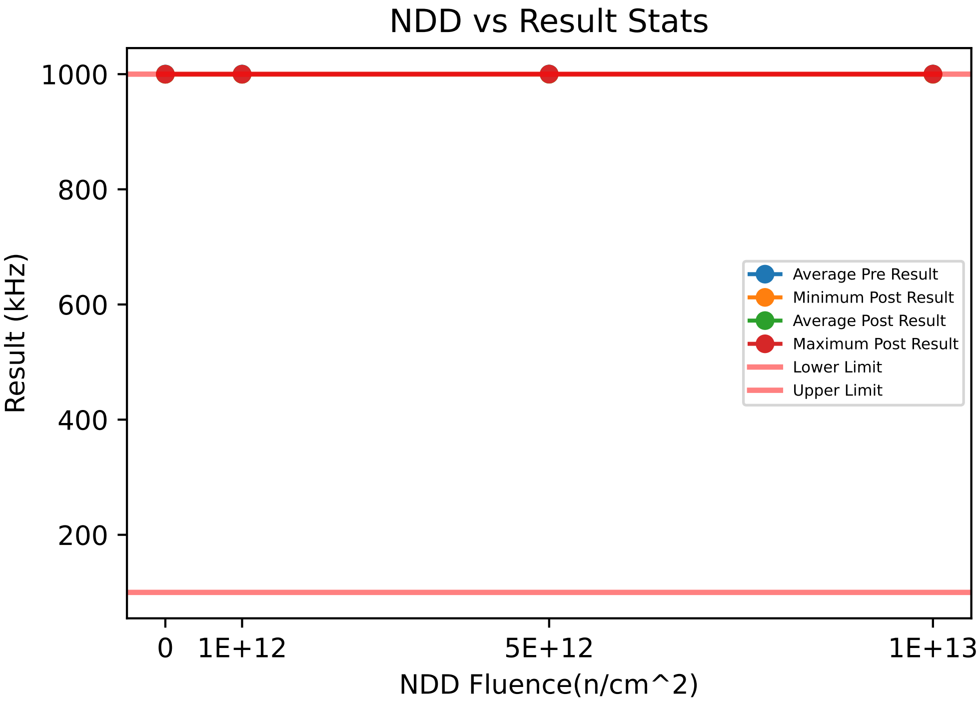
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

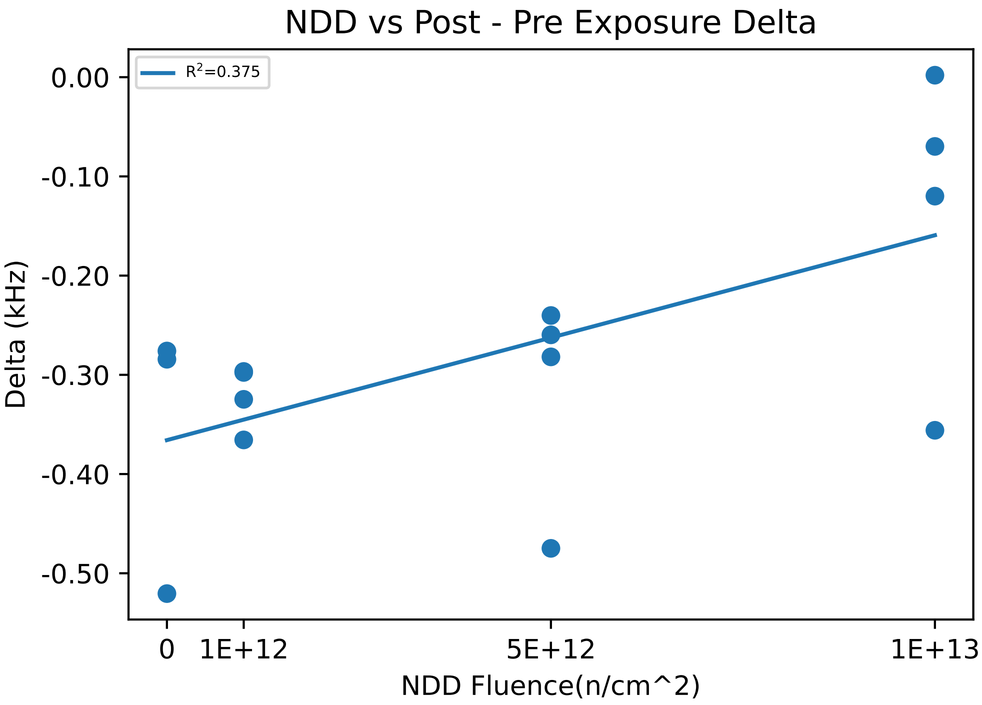
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1010.3	1009.5	-0.778
2	1e+12	NDD	998.03	997.47	-0.5663
3	1e+12	NDD	998.05	997.82	-0.2257
4	1e+12	NDD	1001	1000.3	-0.709
5	5e+12	NDD	979.18	978.9	-0.2815
6	5e+12	NDD	996.35	996.4	0.0464
7	5e+12	NDD	1002.6	1003	0.3716
8	5e+12	NDD	1010.7	1009.9	-0.7628
9	1e+13	NDD	1009.6	1010.3	0.6351
10	1e+13	NDD	1009.8	1009.6	-0.2253
11	1e+13	NDD	1009.3	1008.8	-0.5206
12	1e+13	NDD	1007.3	1007.1	-0.19
13	0	CORRELATION	998.19	997.72	-0.4641
14	0	CORRELATION	1003	1002.7	-0.2842
15	0	CORRELATION	994.8	994.52	-0.2783

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.8	998.65	1003	4.1104	994.52	998.31	1002.7	4.1192	-0.4641	-0.3422	-0.2783	0.10561
1e+12	998.03	1001.8	1010.3	5.7894	997.47	1001.3	1009.5	5.6221	-0.778	-0.56975	-0.2257	0.24572
5e+12	979.18	997.2	1010.7	13.375	978.9	997.05	1009.9	13.302	-0.7628	-0.15658	0.3716	0.48418
1e+13	1007.3	1009	1009.8	1.1761	1007.1	1008.9	1010.3	1.369	-0.5206	-0.0752	0.6351	0.49619

Device Test: 20.98 LEVEL|FREQ/SYNC/5/5/0/1000/5/1MHz//@FREQ_SYNC_EXT





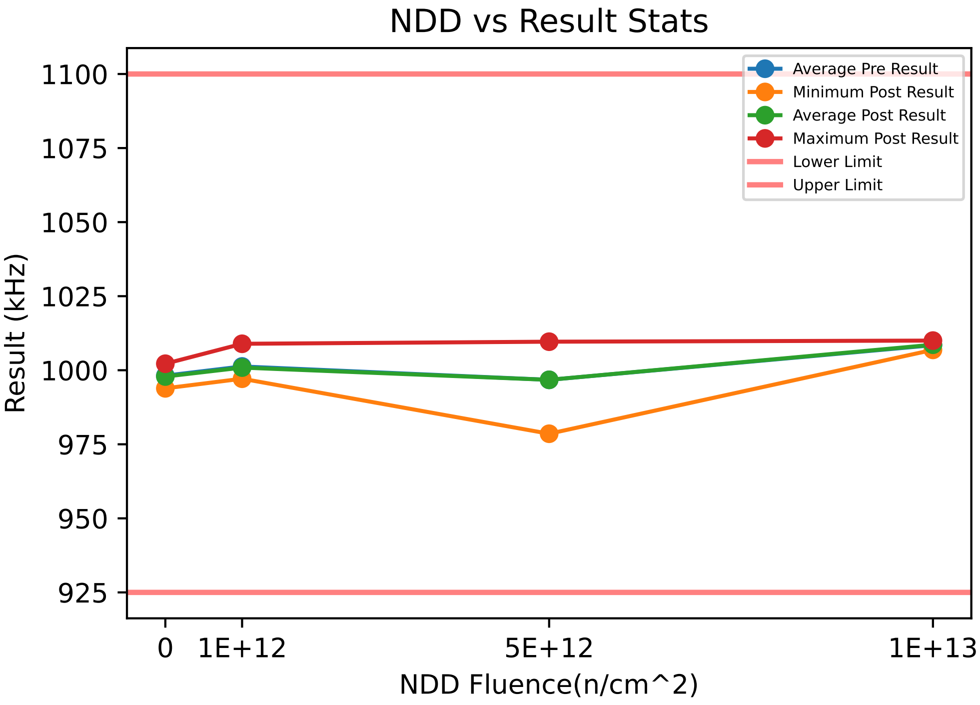
Test Results (Lower Limit = 100.0,
Upper Limit = 1000.0 (kHz))

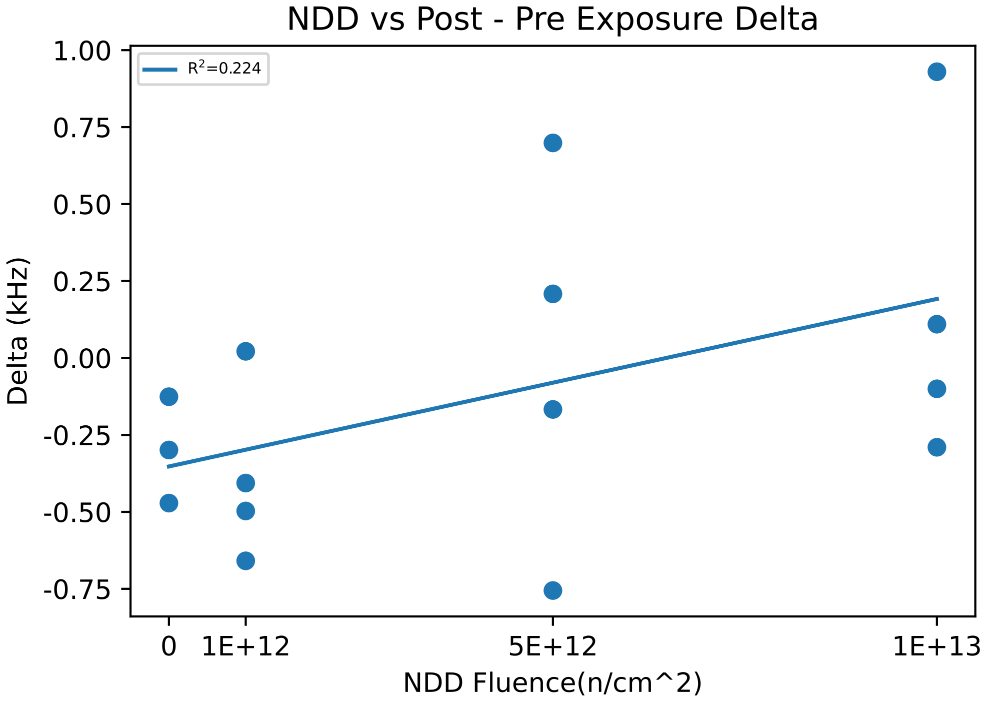
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1000.1	999.73	-0.3656
2	1e+12	NDD	1000.2	999.87	-0.3247
3	1e+12	NDD	1000.2	999.93	-0.2966
4	1e+12	NDD	1000.2	999.92	-0.2976
5	5e+12	NDD	1000.3	999.87	-0.4749
6	5e+12	NDD	1000.2	999.88	-0.2819
7	5e+12	NDD	1000.2	999.92	-0.2597
8	5e+12	NDD	1000.3	1000.1	-0.2402
9	1e+13	NDD	1000.2	1000.1	-0.0698
10	1e+13	NDD	1000.1	999.72	-0.3559
11	1e+13	NDD	1000.1	1000.1	0.002
12	1e+13	NDD	1000.2	1000.1	-0.1199
13	0	CORRELATION	1000.2	999.72	-0.5205
14	0	CORRELATION	1000.1	999.83	-0.2843
15	0	CORRELATION	1000.2	999.89	-0.276

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1000.1	1000.2	1000.2	0.06257	999.72	999.82	999.89	0.08696	-0.5205	-0.36027	-0.276	0.13883
1e+12	1000.1	1000.2	1000.2	0.060835	999.73	999.86	999.93	0.092739	-0.3656	-0.32112	-0.2966	0.032382
5e+12	1000.2	1000.3	1000.3	0.091837	999.87	999.94	1000.1	0.094865	-0.4749	-0.31418	-0.2402	0.1085
1e+13	1000.1	1000.1	1000.2	0.070999	999.72	1000	1000.1	0.1924	-0.3559	-0.1359	0.002	0.15496

Device Test: 20.99 LEVEL|FREQ/RT/12/12/0/1000/5/1MHz//@FSW_EXT_RT_D





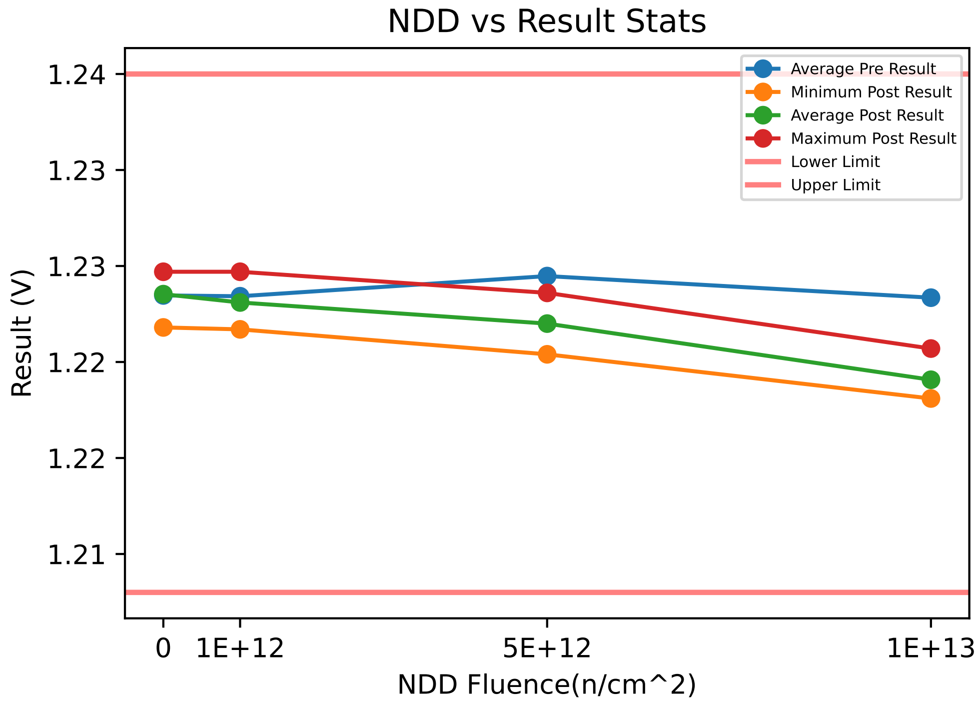
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

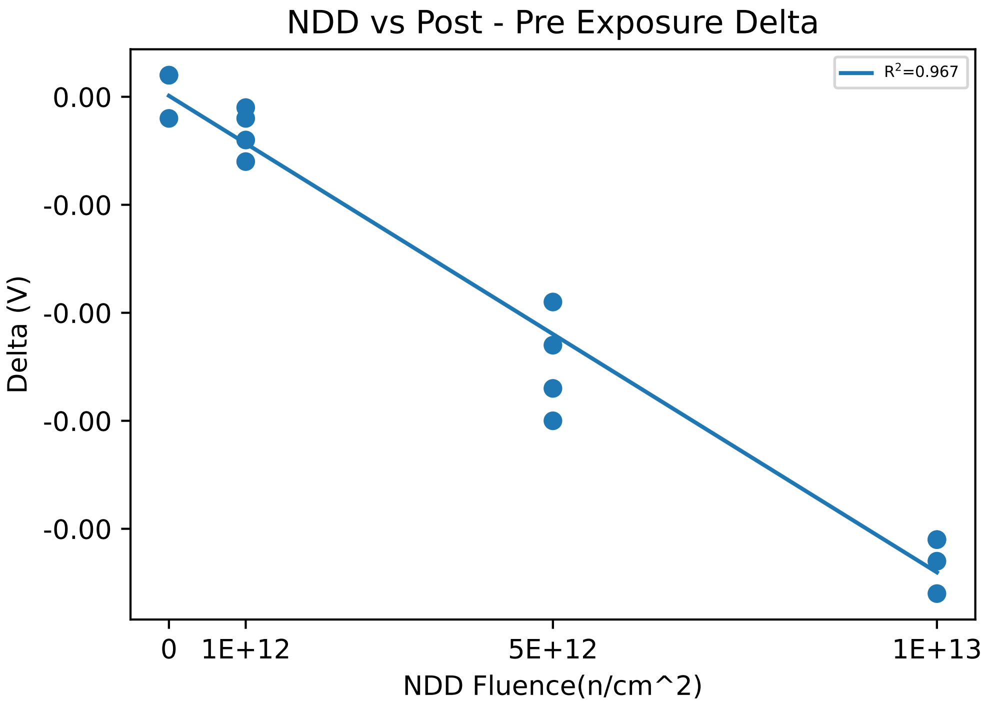
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1009.6	1008.9	-0.6591
2	1e+12	NDD	997.63	997.13	-0.4971
3	1e+12	NDD	997.53	997.55	0.0216
4	1e+12	NDD	1000.4	999.95	-0.4064
5	5e+12	NDD	978.73	978.56	-0.1672
6	5e+12	NDD	995.73	995.93	0.2082
7	5e+12	NDD	1002.2	1002.9	0.6986
8	5e+12	NDD	1010.4	1009.6	-0.7555
9	1e+13	NDD	1009.1	1010	0.9298
10	1e+13	NDD	1009.2	1009.1	-0.1002
11	1e+13	NDD	1008.8	1008.5	-0.2901
12	1e+13	NDD	1006.8	1006.9	0.1097
13	0	CORRELATION	997.83	997.53	-0.299
14	0	CORRELATION	1002.3	1002.2	-0.1259
15	0	CORRELATION	994.35	993.88	-0.4715

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	994.35	998.17	1002.3	3.9936	993.88	997.87	1002.2	4.1659	-0.4715	-0.2988	-0.1259	0.1728
1e+12	997.53	1001.3	1009.6	5.6934	997.13	1000.9	1008.9	5.5001	-0.6591	-0.38525	0.0216	0.29068
5e+12	978.73	996.76	1010.4	13.437	978.56	996.76	1009.6	13.359	-0.7555	-0.003975	0.6986	0.61375
1e+13	1006.8	1008.4	1009.2	1.1335	1006.9	1008.6	1010	1.314	-0.2901	0.1623	0.9298	0.53709

Device Test: 21.1 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/100kHz//@V_REFCAP





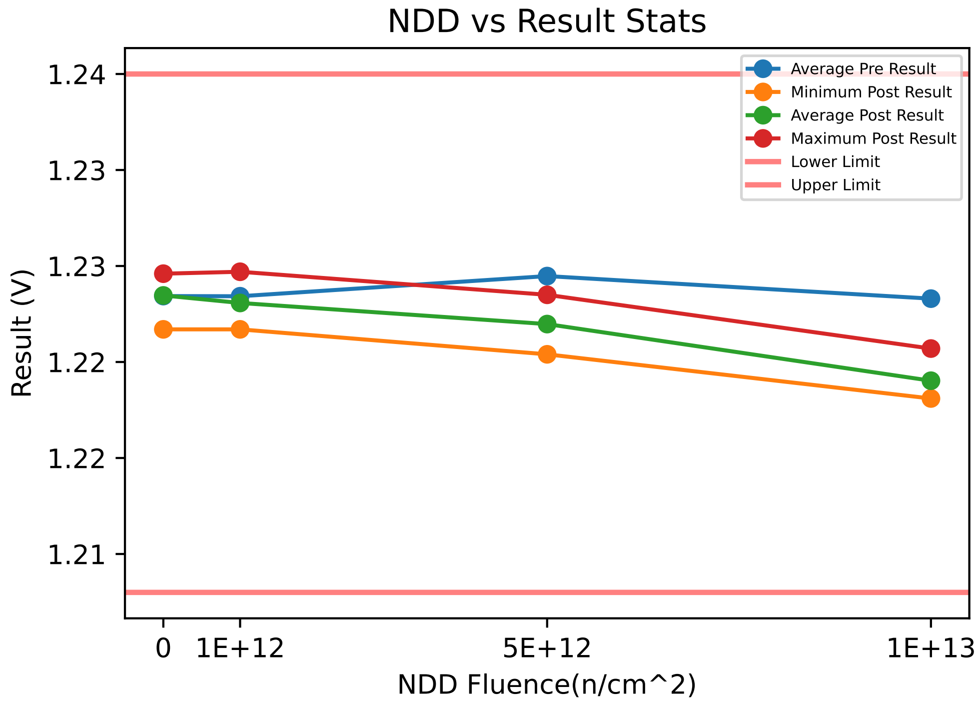
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

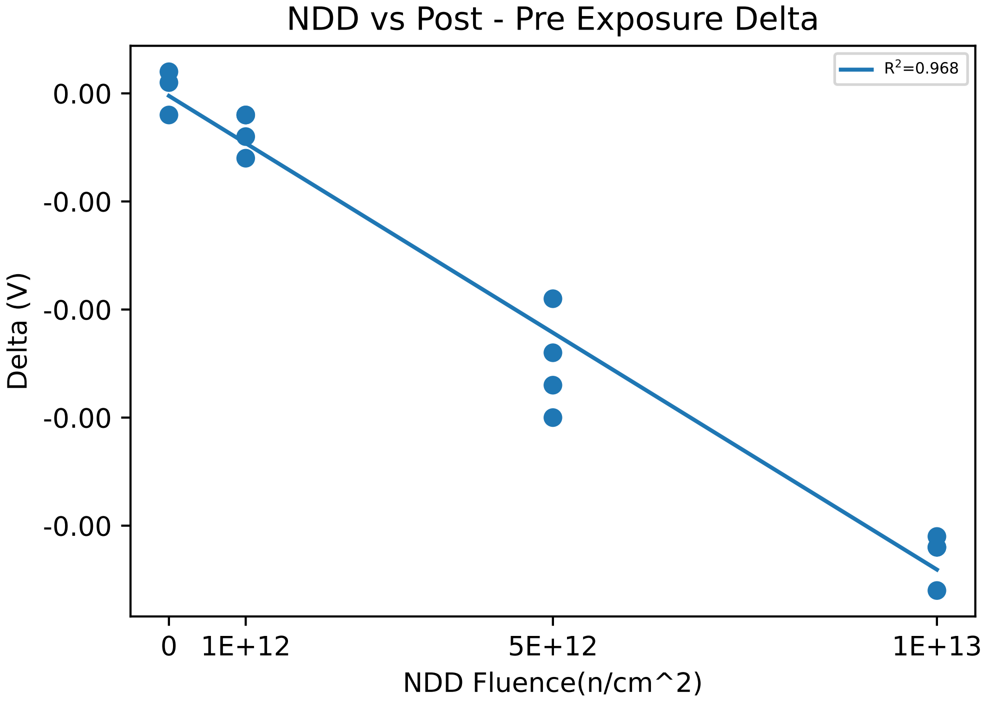
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2236	-0.0023
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2247	0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2245	0.0016197	1.2218	1.2235	1.2247	0.0015308	-0.0002	6.6667e-05	0.0002	0.00023094
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2217	1.2231	1.2247	0.0012329	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2236	0.0013166	-0.003	-0.002475	-0.0019	0.00047871
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.2191	1.2207	0.0011325	-0.0046	-0.004275	-0.0041	0.00023629

Device Test: 21.11 VOLTAGE|VREF/VREF/5/5/0/0/5/500kHz//@V_REFCAP





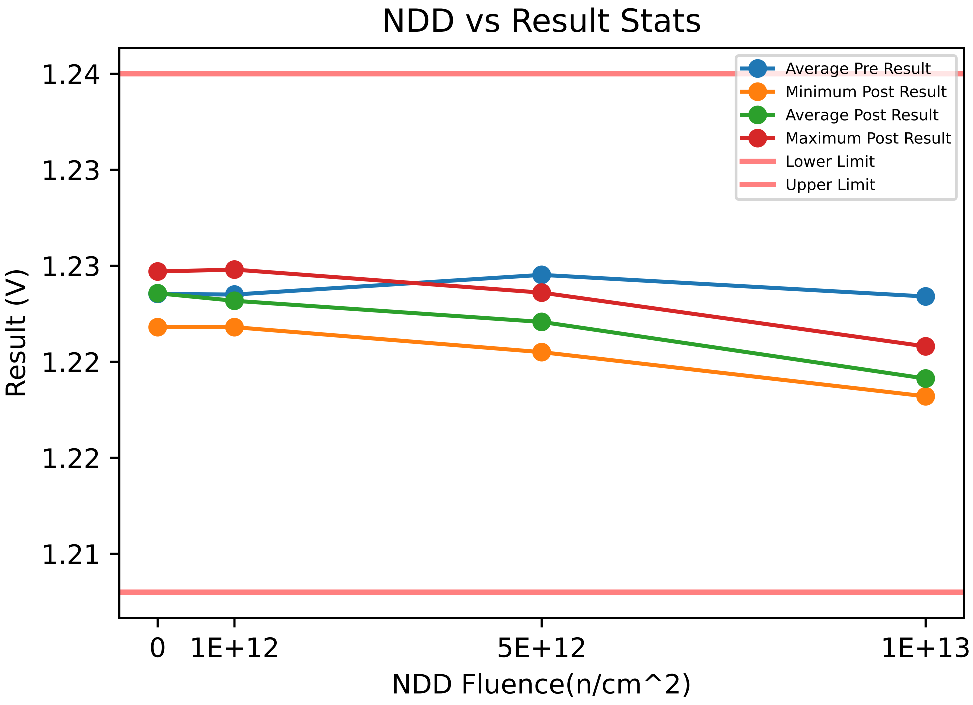
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

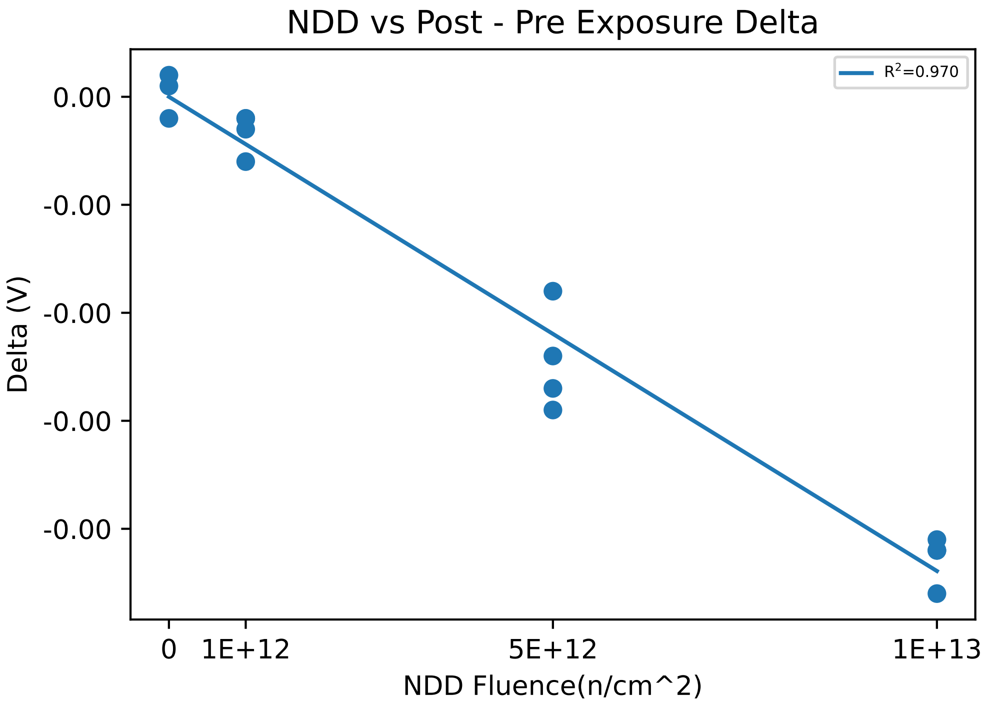
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2228	-0.0002
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2217	1.2235	1.2246	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2217	1.2231	1.2247	0.0012393	-0.0006	-0.00035	-0.0002	0.00019149
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2235	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2223	1.2233	1.2253	0.0013638	1.2181	1.219	1.2207	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.13 VOLTAGE|VREF/VREF/12/12/0/0/5/500kHz//@V_REFCAP


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

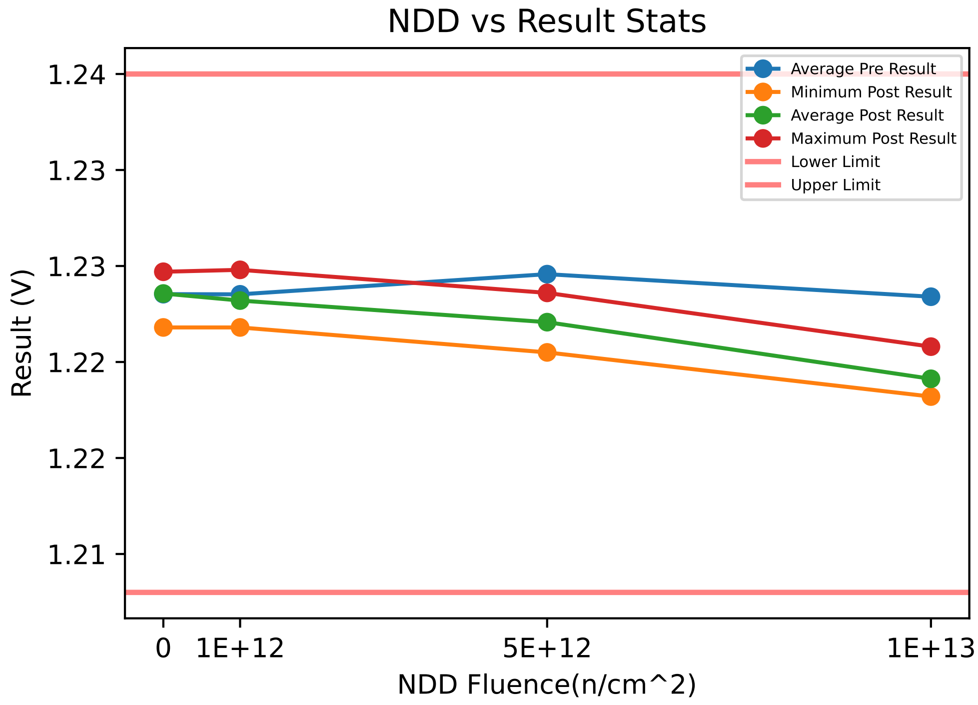
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

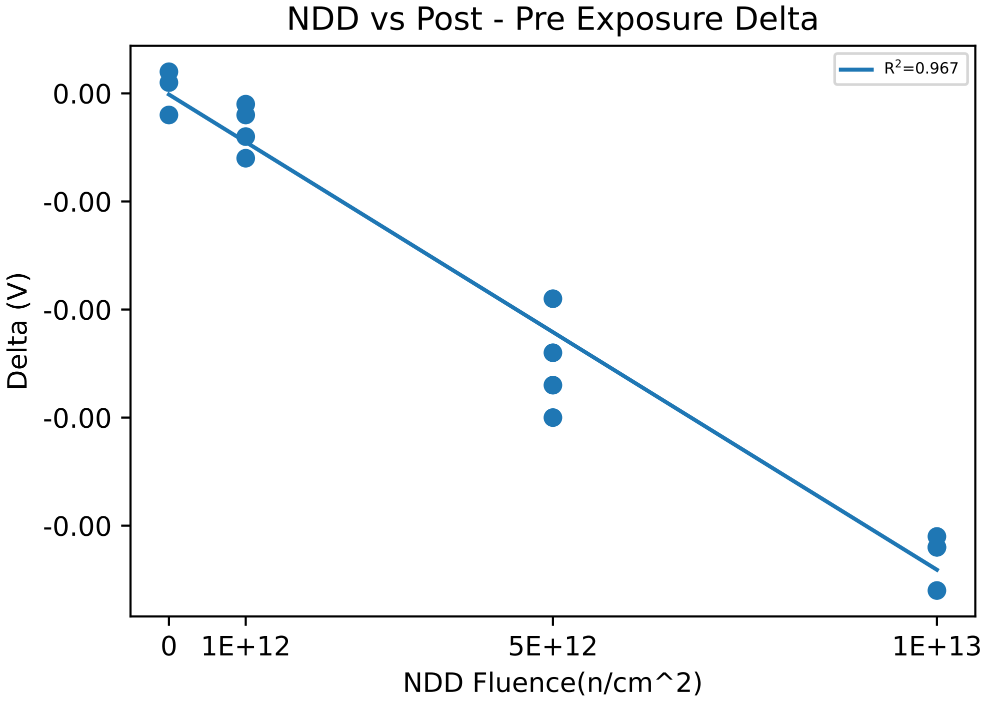
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.2229	-0.0002
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.225	1.2248	-0.0002
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2241	1.2223	-0.0018
8	5e+12	NDD	1.2234	1.2205	-0.0029
9	1e+13	NDD	1.2224	1.2182	-0.0042
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.2231	1.2189	-0.0042
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2221	1.2235	1.225	0.0012193	1.2218	1.2232	1.2248	0.0012393	-0.0006	-0.000325	-0.0002	0.0001893
5e+12	1.2234	1.2245	1.226	0.0010996	1.2205	1.2221	1.2236	0.0012764	-0.0029	-0.00245	-0.0018	0.00047958
1e+13	1.2224	1.2234	1.2254	0.0013638	1.2182	1.2191	1.2208	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.15 VOLTAGE|VREF/VREF/14/14/0/0/5/500kHz//@V_REFCAP





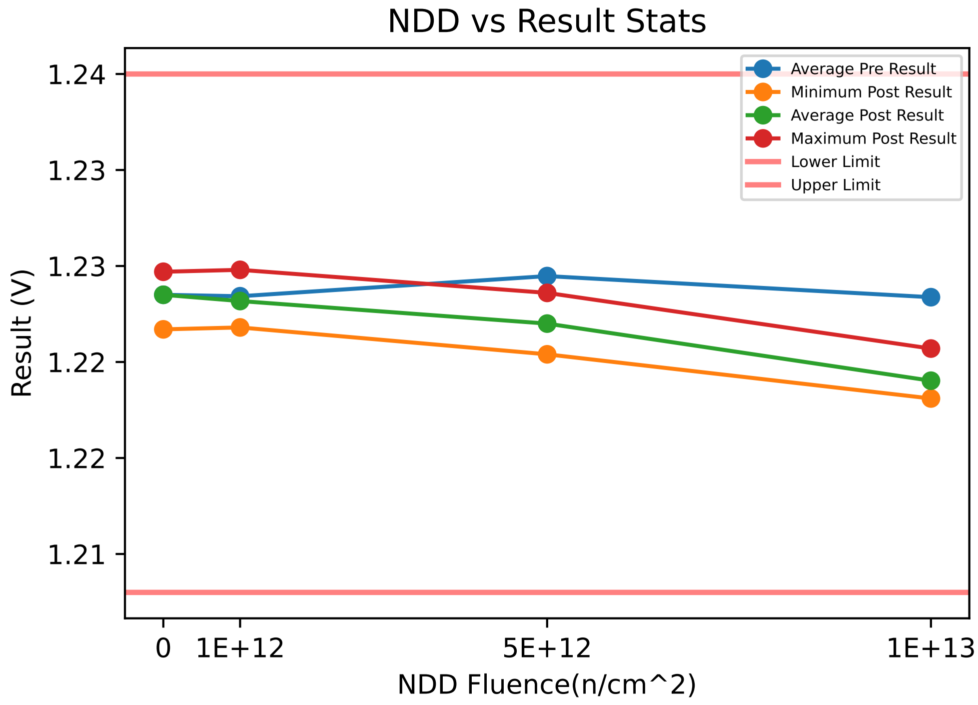
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

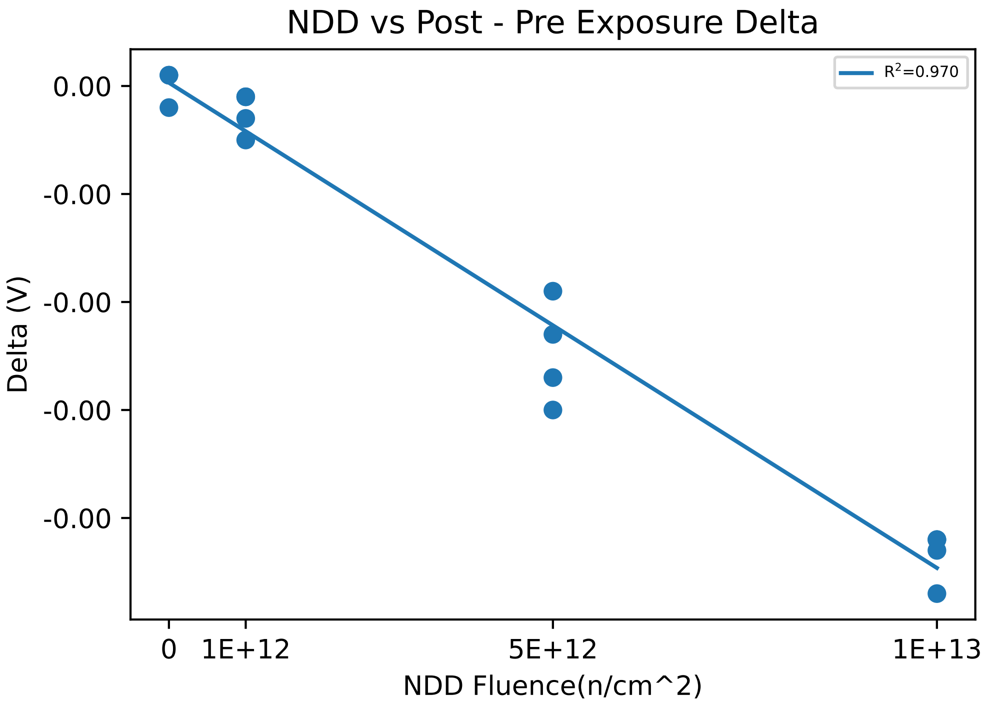
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.223	-0.0001
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2222	1.2218	-0.0004
4	1e+12	NDD	1.225	1.2248	-0.0002
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2205	-0.003
9	1e+13	NDD	1.2224	1.2182	-0.0042
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.2231	1.2189	-0.0042
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2222	1.2235	1.225	0.0011815	1.2218	1.2232	1.2248	0.0012329	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2235	1.2246	1.226	0.0010532	1.2205	1.2221	1.2236	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2224	1.2234	1.2254	0.0013638	1.2182	1.2191	1.2208	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.17 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/1MHz//@V_REFCAP





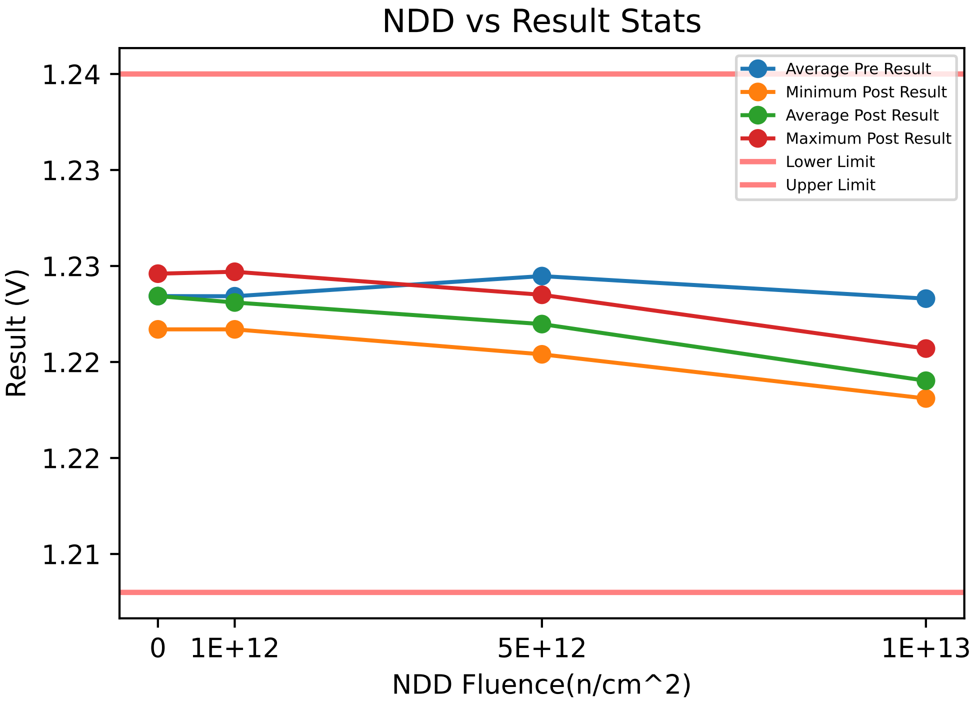
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

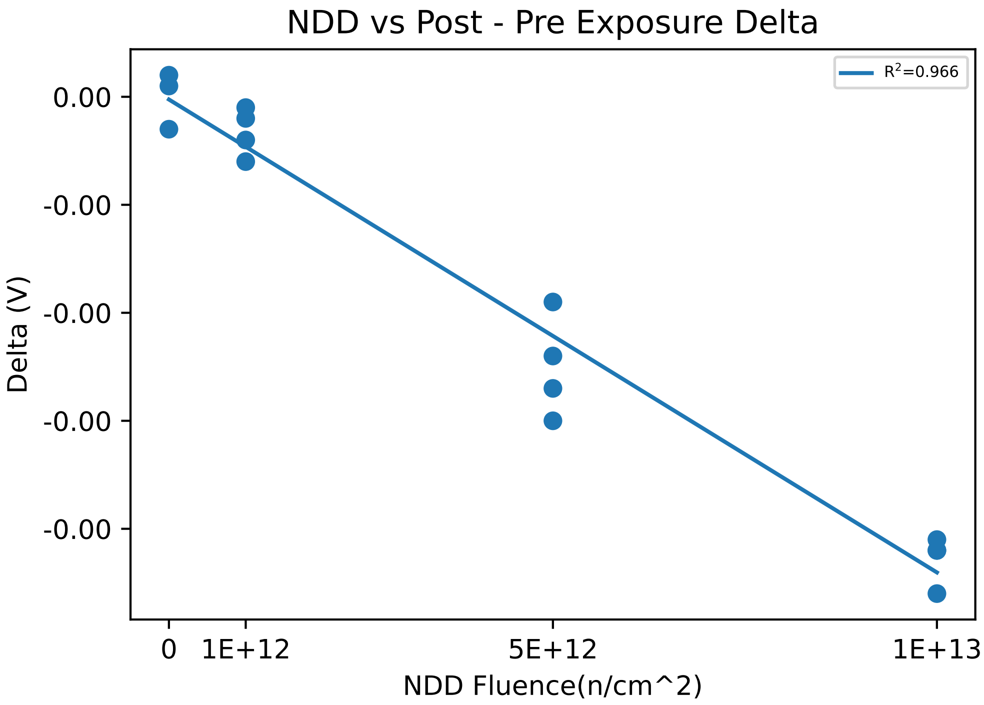
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2248	-0.0001
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2236	-0.0023
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2254	1.2207	-0.0047
13	0	CORRELATION	1.2216	1.2217	0.0001
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016523	1.2217	1.2235	1.2247	0.0015875	-0.0002	0	0.0001	0.00017321
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2218	1.2232	1.2248	0.0012393	-0.0005	-0.00025	-0.0001	0.00019149
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2236	0.0013166	-0.003	-0.002475	-0.0019	0.00047871
1e+13	1.2224	1.2234	1.2254	0.001372	1.2181	1.219	1.2207	0.0011529	-0.0047	-0.00435	-0.0042	0.00023805

Device Test: 21.19 VOLTAGE|VREF/VREF/5/5/0/0/5/1MHz//@V_REFCAP





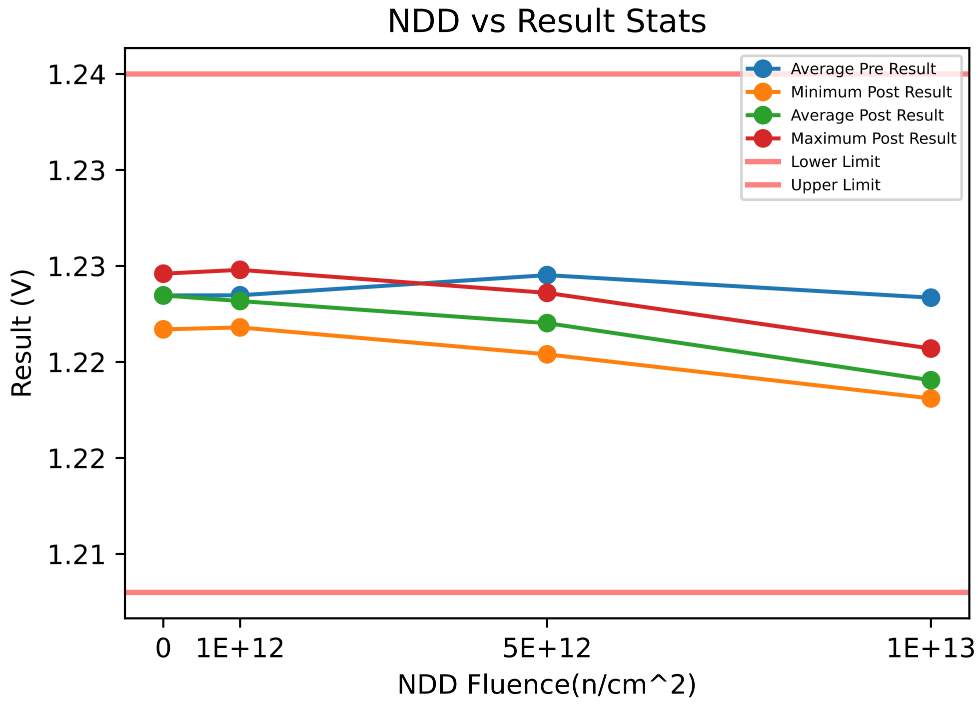
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

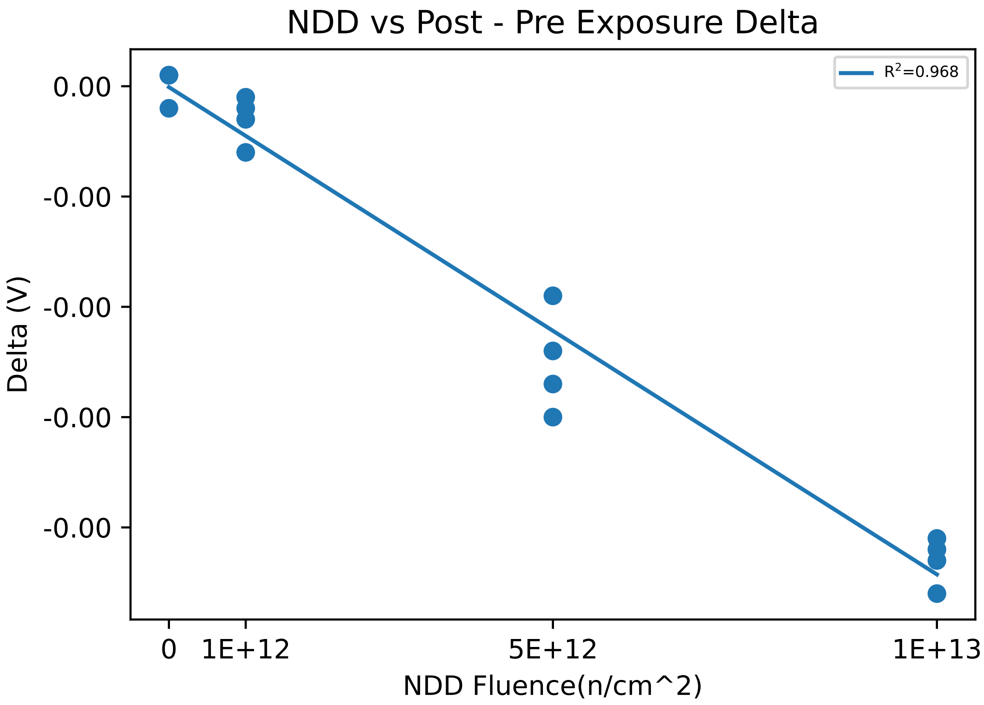
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.224	-0.0003
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2217	1.2234	1.2246	0.0015308	-0.0003	0	0.0002	0.00026458
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2217	1.2231	1.2247	0.0012329	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2235	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2223	1.2233	1.2253	0.0013638	1.2181	1.219	1.2207	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.21 VOLTAGE|VREF/VREF/12/12/0/0/5/1MHz//@V_REFCAP


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

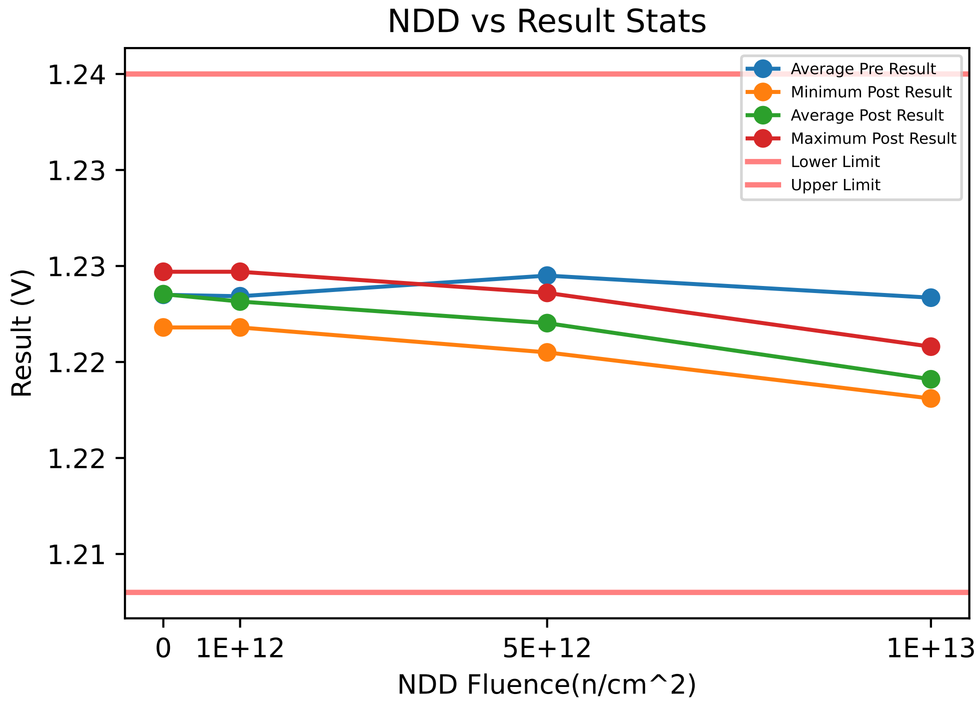
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

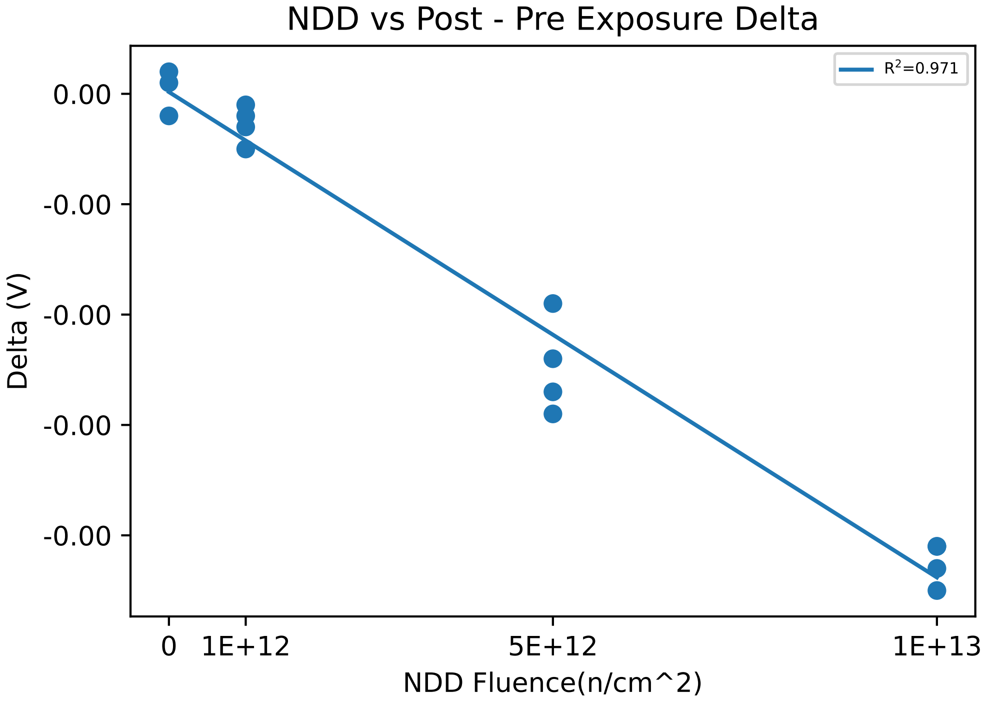
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.2229	-0.0002
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2248	-0.0001
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2216	1.2217	0.0001
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2245	0.0016197	1.2217	1.2235	1.2246	0.0015503	-0.0002	0	0.0001	0.00017321
1e+12	1.2221	1.2235	1.2249	0.0011786	1.2218	1.2232	1.2248	0.0012393	-0.0006	-0.0003	-0.0001	0.00021602
5e+12	1.2234	1.2245	1.226	0.0010996	1.2204	1.222	1.2236	0.0013124	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.219	1.2207	0.0011475	-0.0046	-0.0043	-0.0041	0.00021602

Device Test: 21.23 VOLTAGE|VREF/VREF/14/14/0/0/5/1MHz//@V_REFCAP





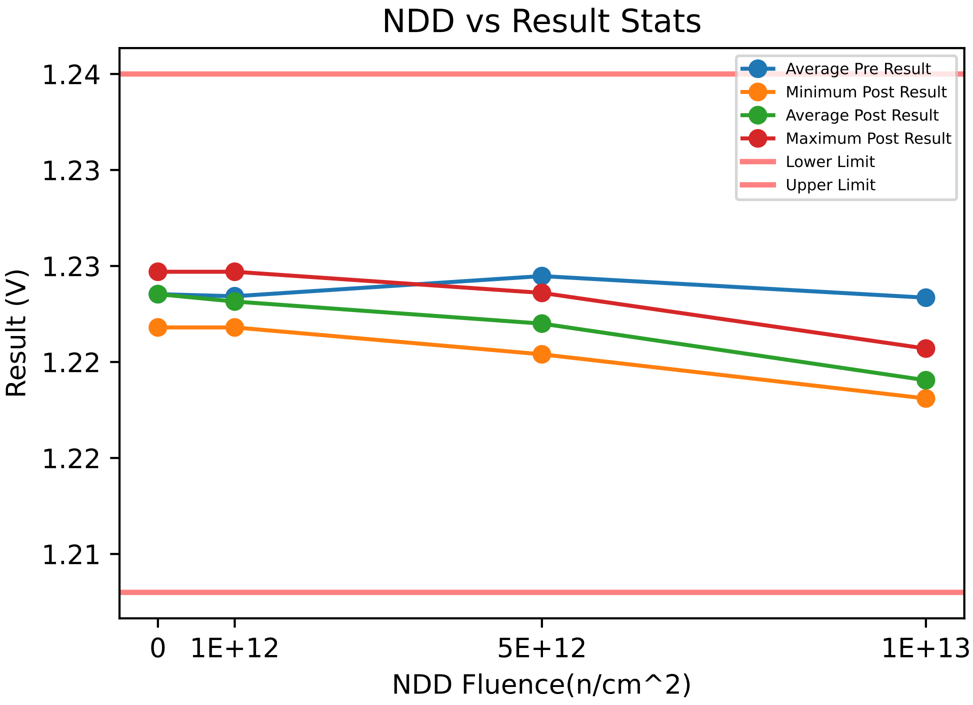
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

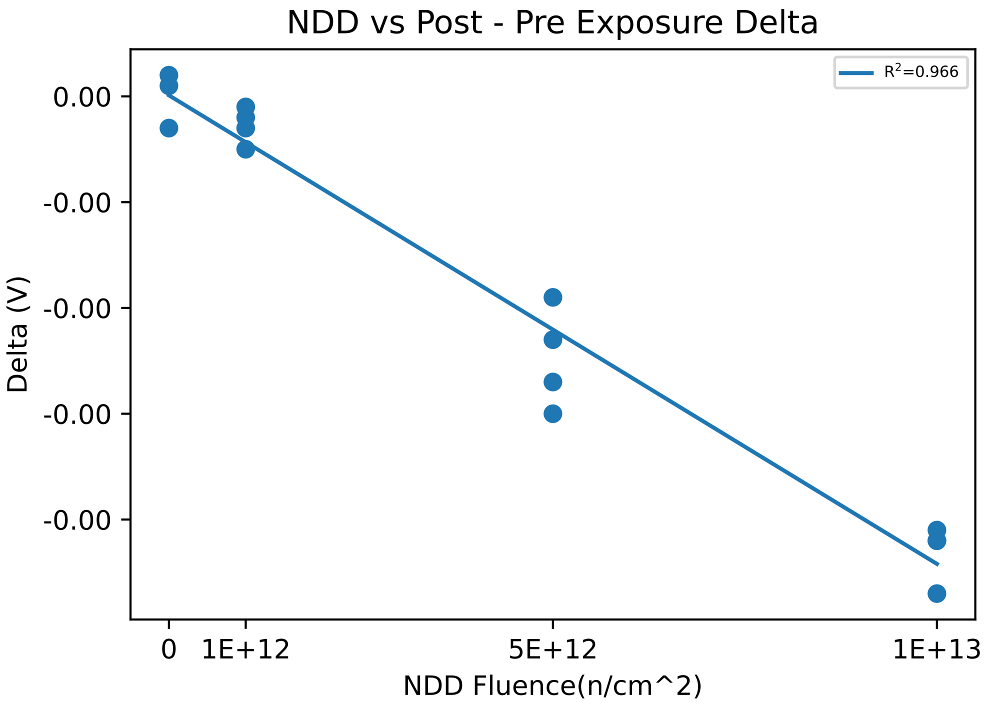
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2205	-0.0029
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2208	-0.0045
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016523	1.2218	1.2235	1.2247	0.0015308	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2218	1.2231	1.2247	0.0011958	-0.0005	-0.000275	-0.0001	0.00017078
5e+12	1.2234	1.2245	1.226	0.0010985	1.2205	1.222	1.2236	0.0012764	-0.0029	-0.002475	-0.0019	0.00043493
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.2191	1.2208	0.0011804	-0.0045	-0.00425	-0.0041	0.00019149

Device Test: 21.25 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/100kHz//@V_REFCAP





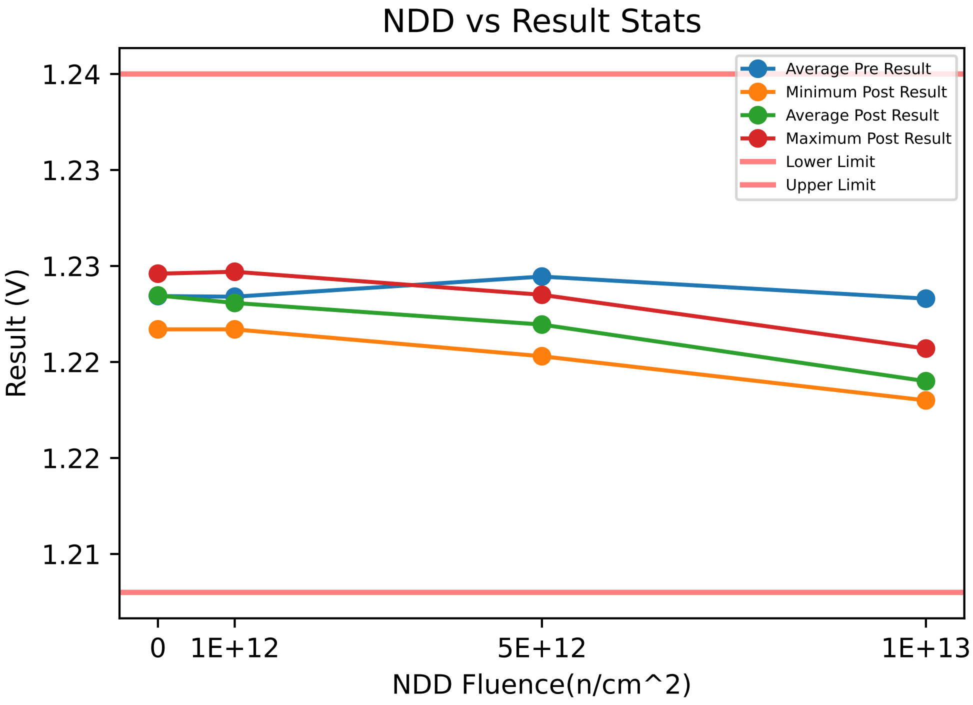
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

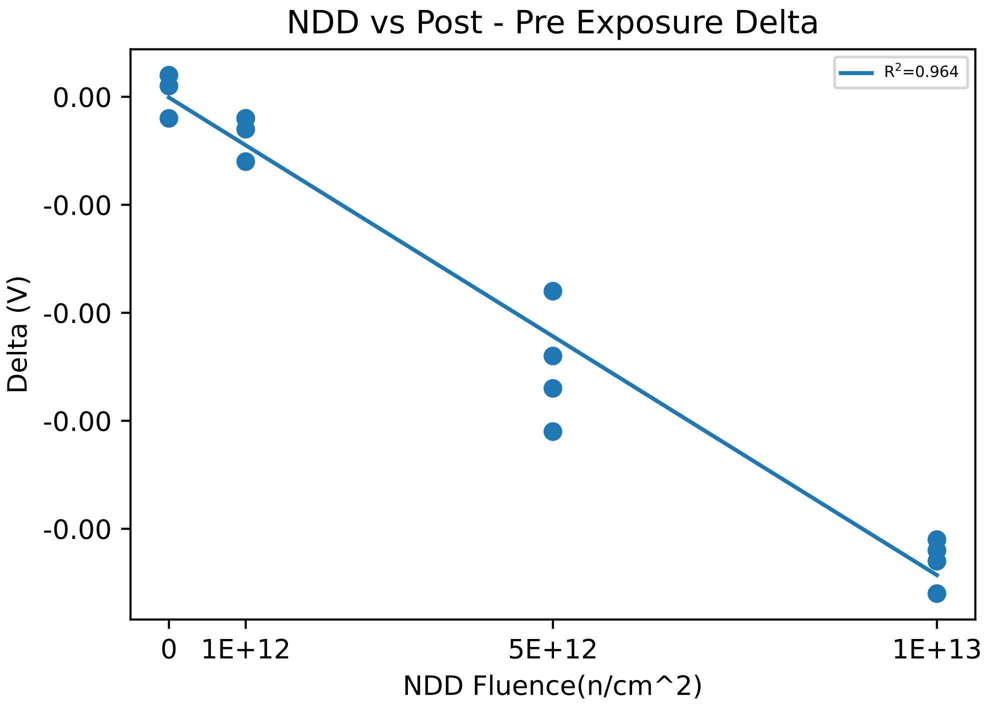
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2236	-0.0023
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2254	1.2207	-0.0047
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2241	-0.0003
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2235	1.2247	0.0015308	-0.0003	0	0.0002	0.00026458
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2218	1.2231	1.2247	0.0011958	-0.0005	-0.000275	-0.0001	0.00017078
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2236	0.0013166	-0.003	-0.002475	-0.0019	0.00047871
1e+13	1.2223	1.2233	1.2254	0.0013964	1.2181	1.219	1.2207	0.0011475	-0.0047	-0.0043	-0.0041	0.0002708

Device Test: 21.27 VOLTAGE|VREF/VREF/5/5/0/1000/5/100kHz//@V_REFCAP





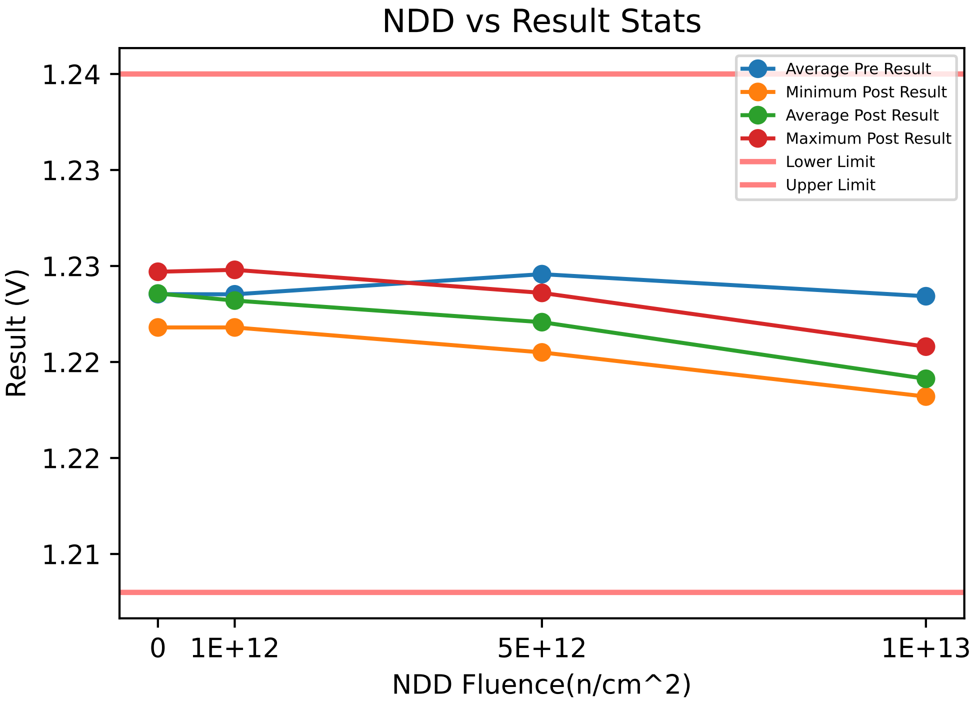
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

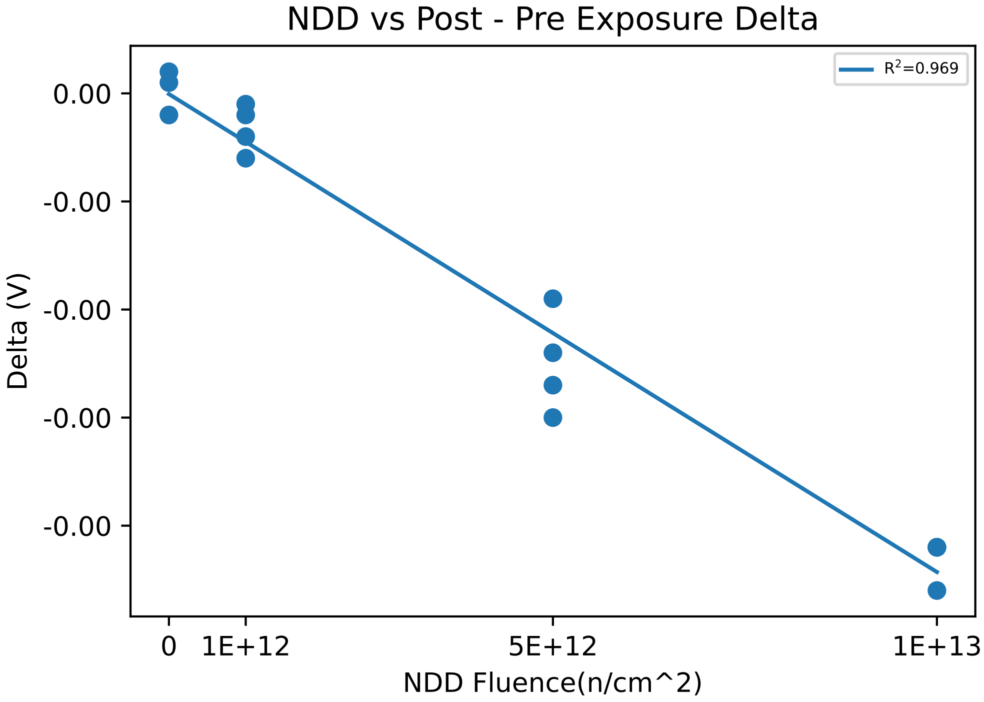
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2228	-0.0002
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.222	1.2217	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.224	1.2222	-0.0018
8	5e+12	NDD	1.2234	1.2203	-0.0031
9	1e+13	NDD	1.2223	1.218	-0.0043
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2217	1.2235	1.2246	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.222	1.2234	1.2249	0.0012193	1.2217	1.2231	1.2247	0.0012393	-0.0006	-0.000325	-0.0002	0.0001893
5e+12	1.2234	1.2245	1.2259	0.0010661	1.2203	1.222	1.2235	0.0013178	-0.0031	-0.0025	-0.0018	0.00054772
1e+13	1.2223	1.2233	1.2253	0.0013638	1.218	1.219	1.2207	0.0011804	-0.0046	-0.0043	-0.0041	0.00021602

Device Test: 21.29 VOLTAGE|VREF/VREF/12/12/0/1000/5/100kHz//@V_REFCAP





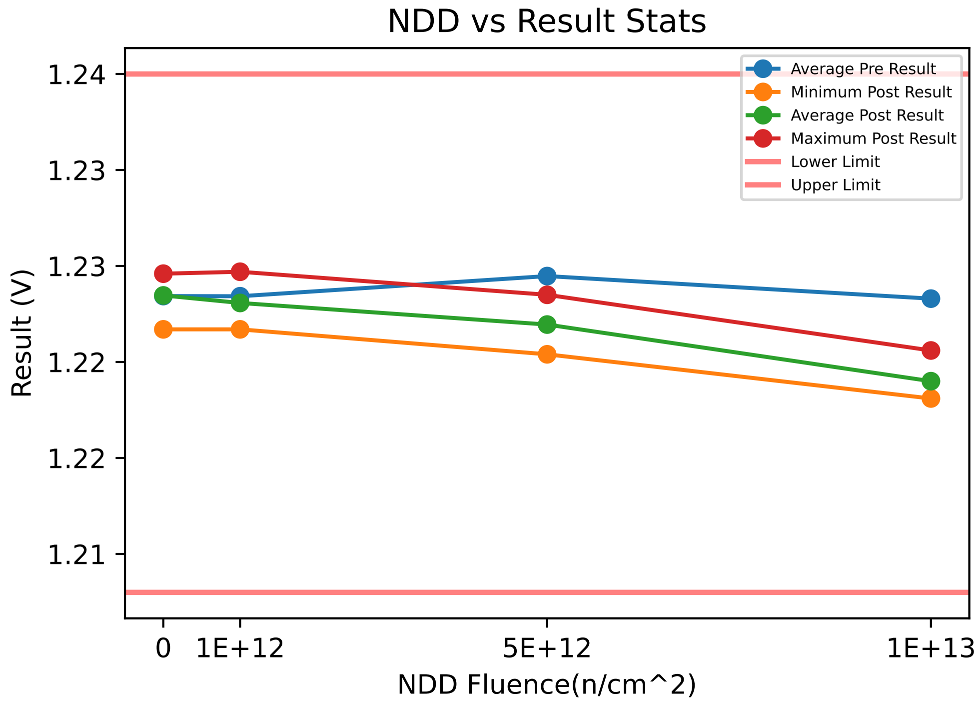
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

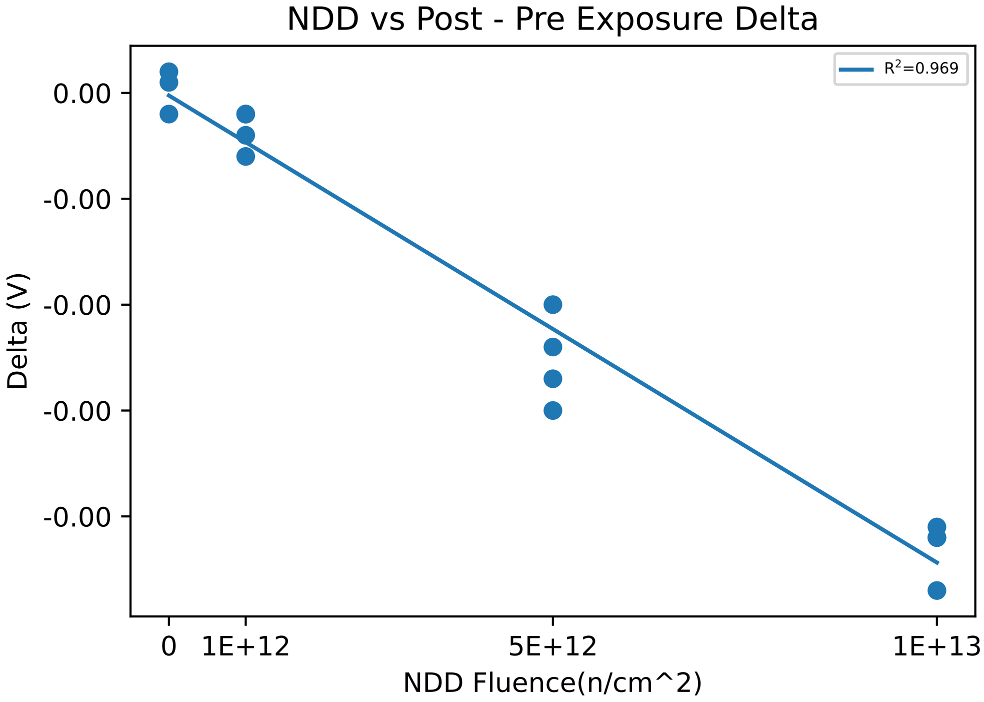
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.223	-0.0001
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2222	1.2218	-0.0004
4	1e+12	NDD	1.225	1.2248	-0.0002
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2205	-0.003
9	1e+13	NDD	1.2224	1.2182	-0.0042
10	1e+13	NDD	1.2228	1.2186	-0.0042
11	1e+13	NDD	1.2231	1.2189	-0.0042
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2222	1.2235	1.225	0.0011815	1.2218	1.2232	1.2248	0.0012329	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2235	1.2246	1.226	0.0010532	1.2205	1.2221	1.2236	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2224	1.2234	1.2254	0.0013475	1.2182	1.2191	1.2208	0.0011529	-0.0046	-0.0043	-0.0042	0.0002

Device Test: 21.3 VOLTAGE|VREF/VREF/5/5/0/0/5/100kHz//@V_REFCAP





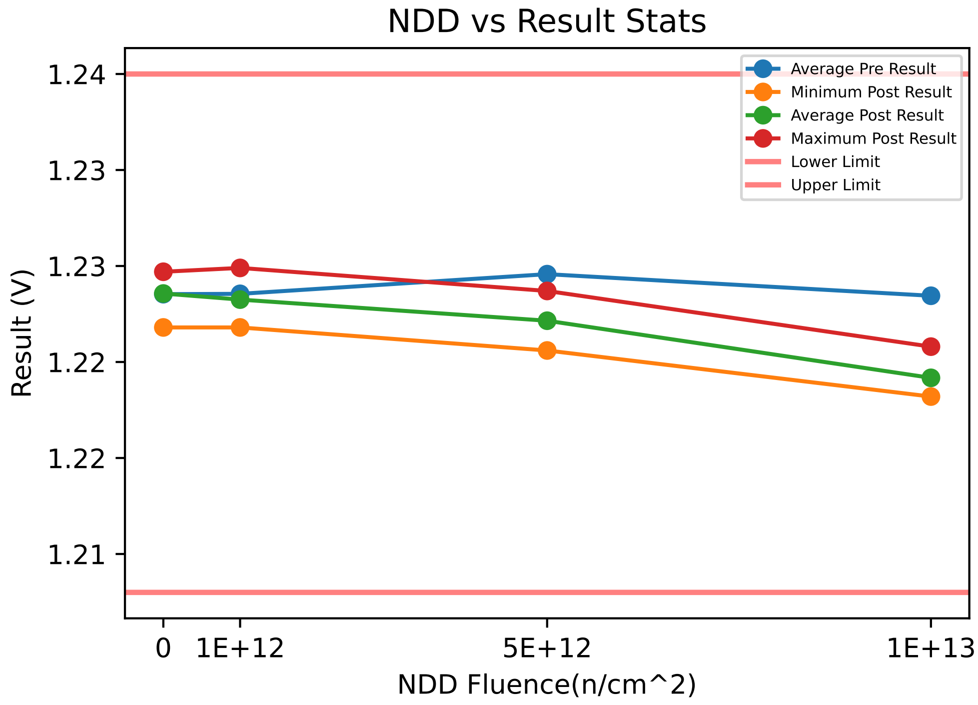
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

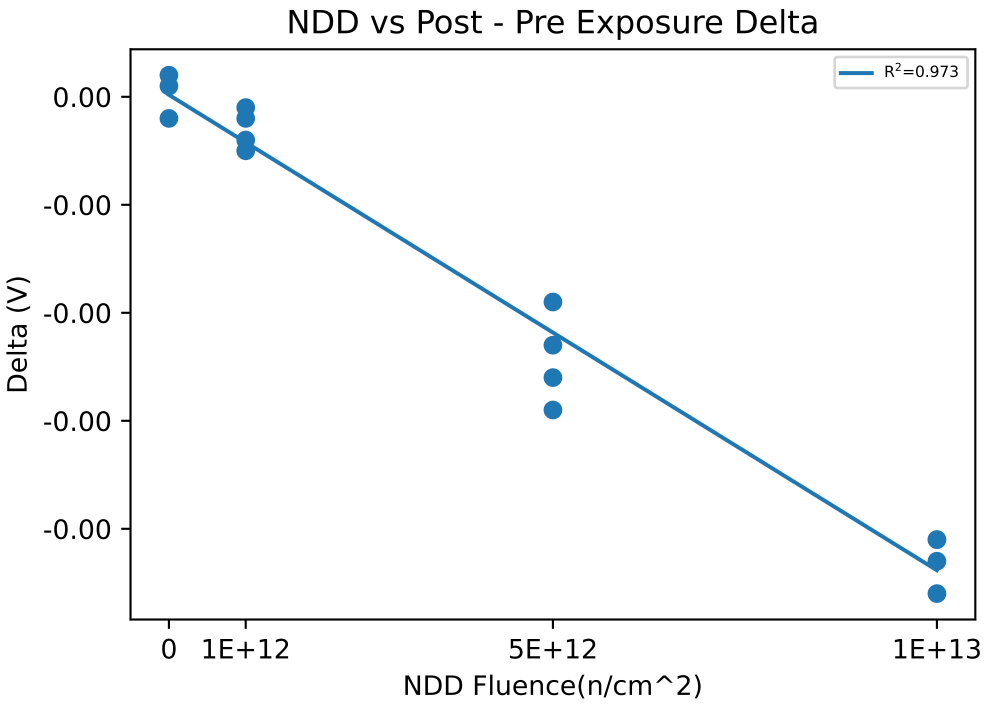
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2228	-0.0002
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.2241	1.2221	-0.002
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2253	1.2206	-0.0047
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2217	1.2235	1.2246	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2217	1.2231	1.2247	0.0012393	-0.0006	-0.00035	-0.0002	0.00019149
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2235	0.0012715	-0.003	-0.002525	-0.002	0.0004272
1e+13	1.2223	1.2233	1.2253	0.0013638	1.2181	1.219	1.2206	0.0011045	-0.0047	-0.0043	-0.0041	0.0002708

Device Test: 21.31 VOLTAGE|VREF/VREF/14/14/0/1000/5/100kHz//@V_REFCAP





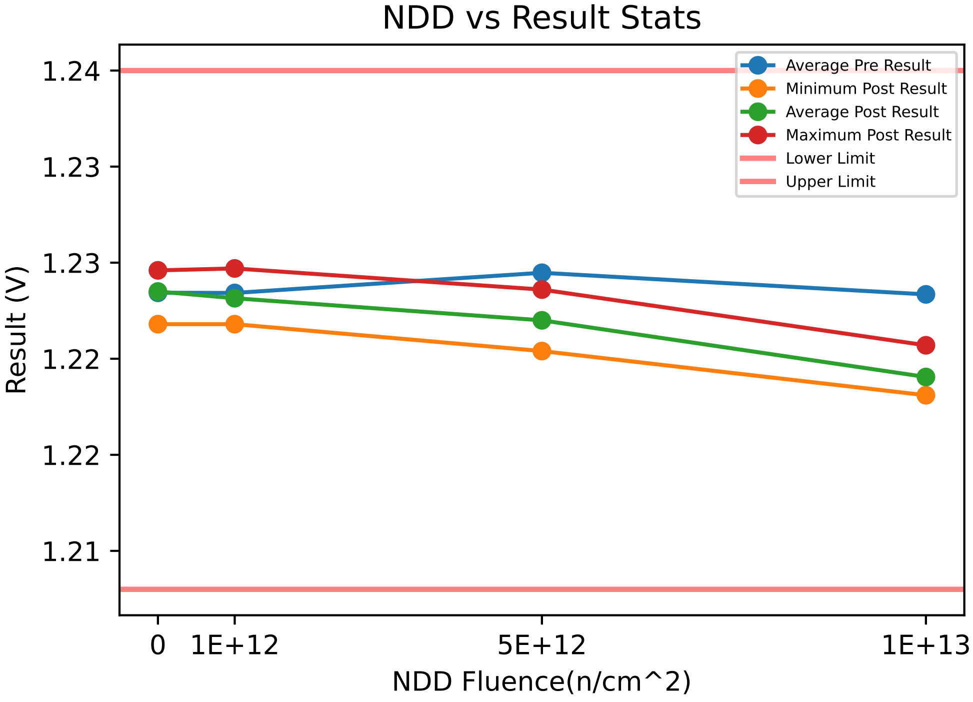
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

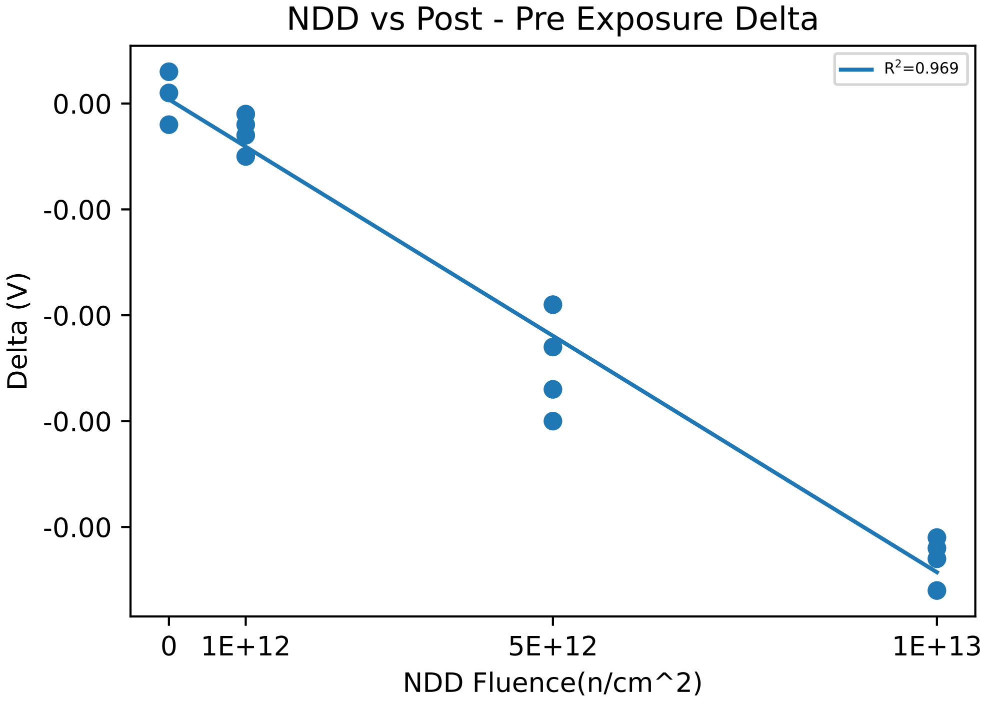
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2232	1.223	-0.0002
2	1e+12	NDD	1.2238	1.2233	-0.0005
3	1e+12	NDD	1.2222	1.2218	-0.0004
4	1e+12	NDD	1.225	1.2249	-0.0001
5	5e+12	NDD	1.2246	1.222	-0.0026
6	5e+12	NDD	1.226	1.2237	-0.0023
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2206	-0.0029
9	1e+13	NDD	1.2225	1.2182	-0.0043
10	1e+13	NDD	1.2228	1.2187	-0.0041
11	1e+13	NDD	1.2231	1.219	-0.0041
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2222	1.2235	1.225	0.0011705	1.2218	1.2233	1.2249	0.0012767	-0.0005	-0.0003	-0.0001	0.00018257
5e+12	1.2235	1.2246	1.226	0.0010532	1.2206	1.2222	1.2237	0.0012715	-0.0029	-0.002425	-0.0019	0.0004272
1e+13	1.2225	1.2235	1.2254	0.0013229	1.2182	1.2192	1.2208	0.0011325	-0.0046	-0.004275	-0.0041	0.00023629

Device Test: 21.33 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/500kHz//@V_REFCAP





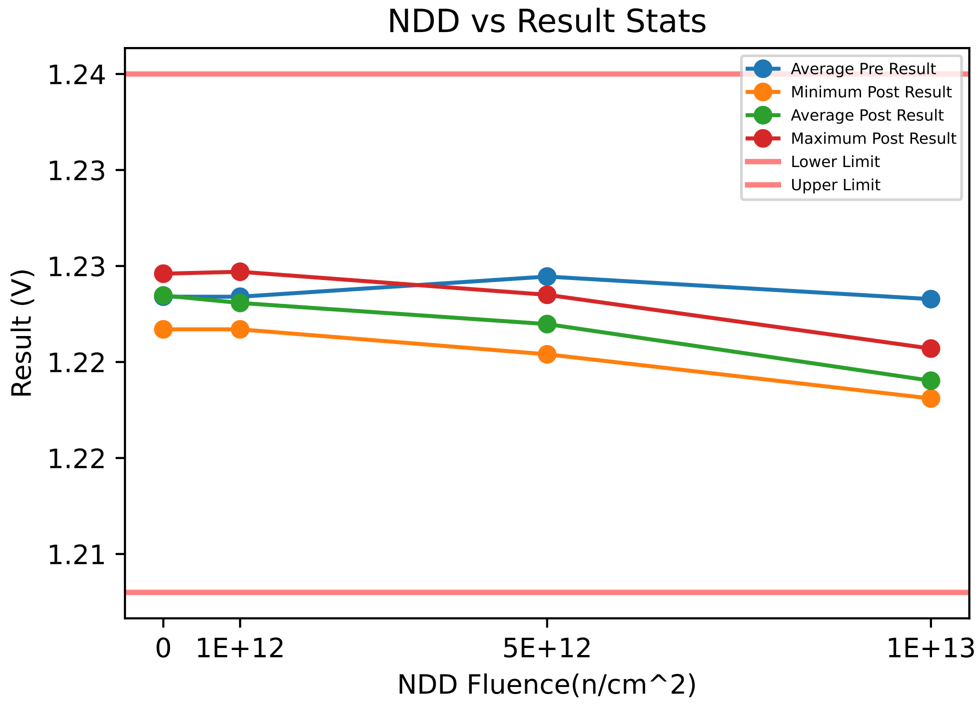
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

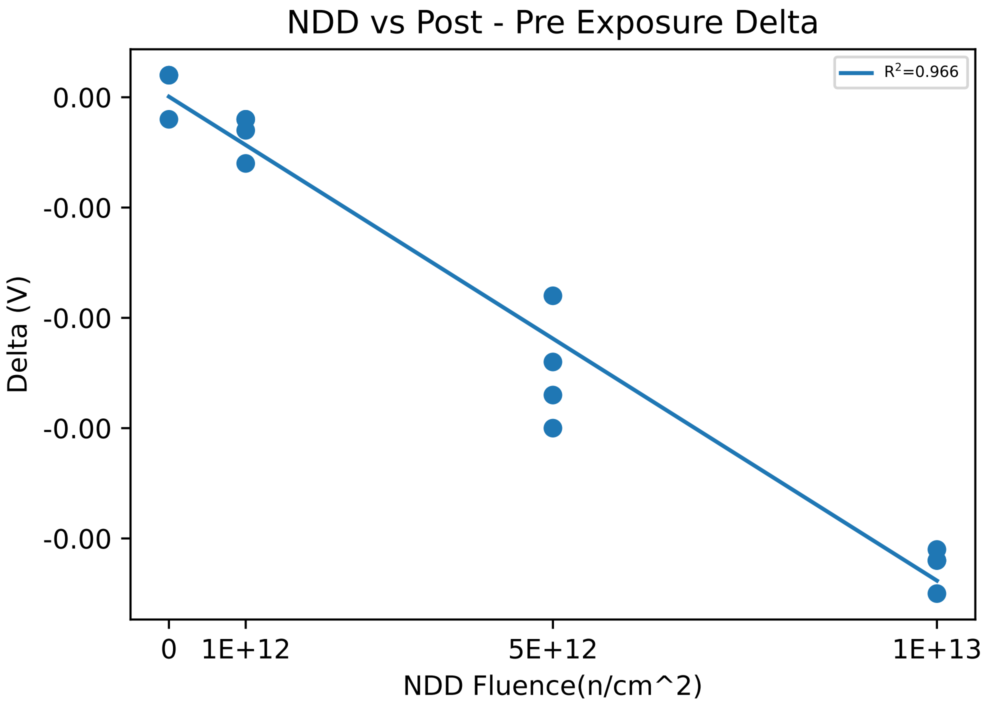
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2236	-0.0023
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2218	0.0003
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2218	1.2235	1.2246	0.0014933	-0.0002	6.6667e-05	0.0003	0.00025166
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2218	1.2231	1.2247	0.0011958	-0.0005	-0.000275	-0.0001	0.00017078
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2236	0.0013166	-0.003	-0.002475	-0.0019	0.00047871
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.219	1.2207	0.0011475	-0.0046	-0.0043	-0.0041	0.00021602

Device Test: 21.35 VOLTAGE|VREF/VREF/5/5/0/1000/5/500kHz//@V_REFCAP





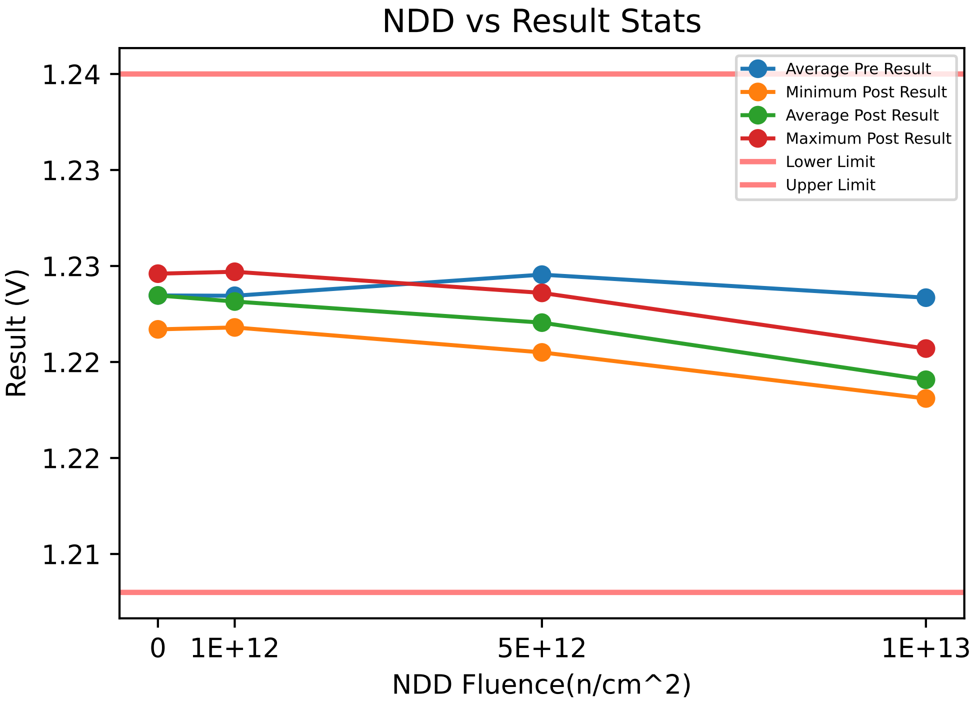
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

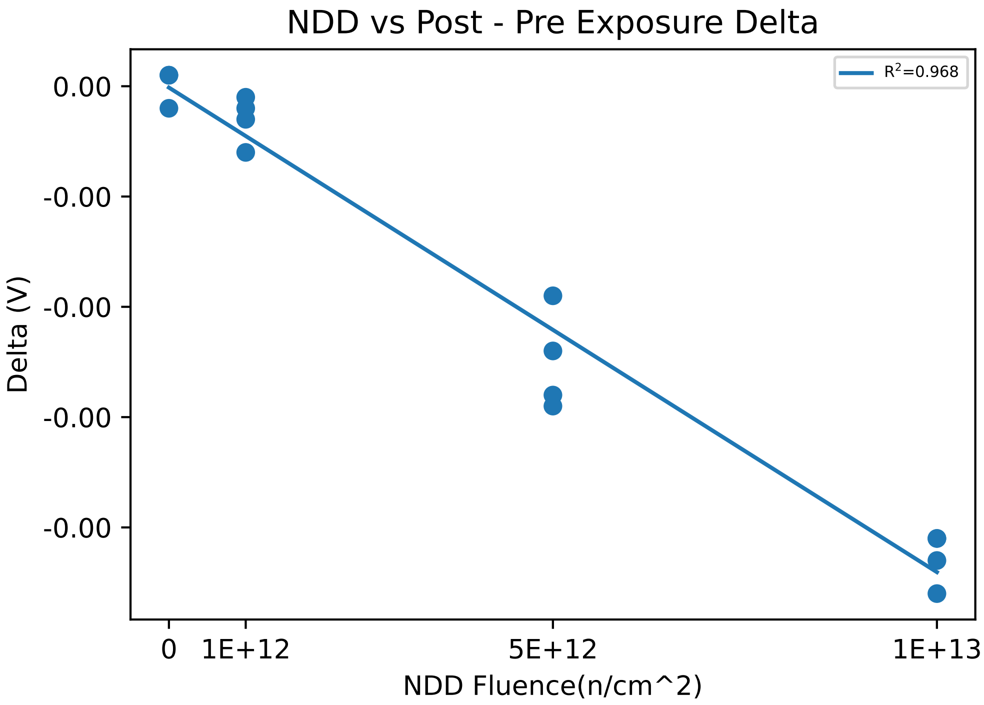
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2228	-0.0002
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.222	1.2217	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.224	1.2222	-0.0018
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2252	1.2207	-0.0045
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2244	1.2246	0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2244	0.0016462	1.2217	1.2235	1.2246	0.0015503	-0.0002	6.6667e-05	0.0002	0.00023094
1e+12	1.222	1.2234	1.2249	0.0012193	1.2217	1.2231	1.2247	0.0012393	-0.0006	-0.000325	-0.0002	0.0001893
5e+12	1.2234	1.2245	1.2259	0.0010661	1.2204	1.222	1.2235	0.0012764	-0.003	-0.002475	-0.0018	0.00051235
1e+13	1.2223	1.2233	1.2252	0.001315	1.2181	1.219	1.2207	0.0011529	-0.0045	-0.00425	-0.0041	0.00017321

Device Test: 21.37 VOLTAGE|VREF/VREF/12/12/0/1000/5/500kHz//@V_REFCAP





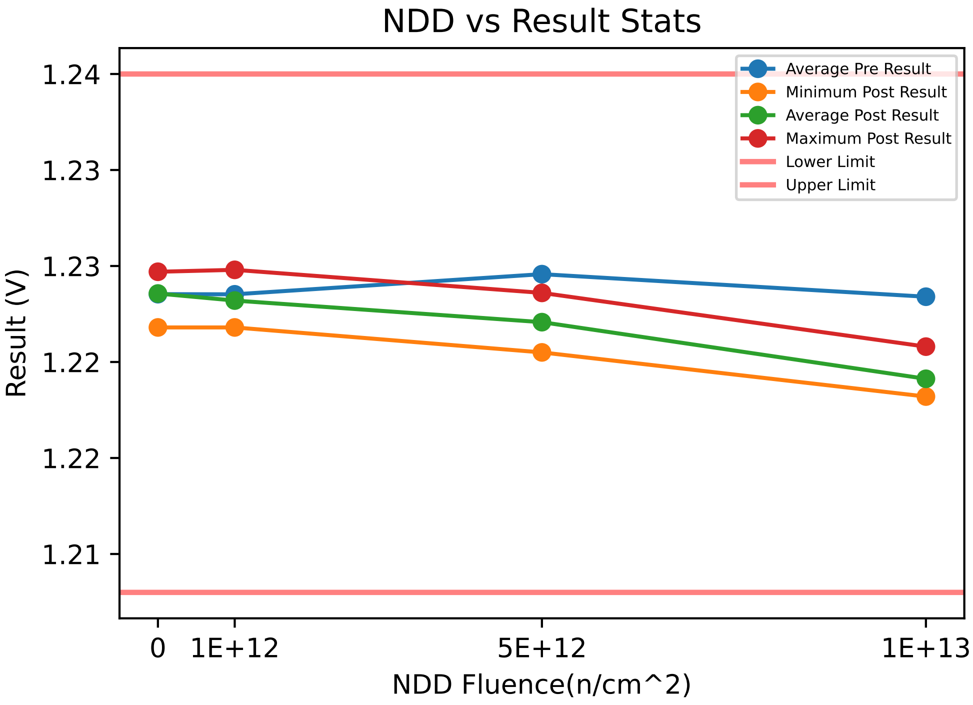
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

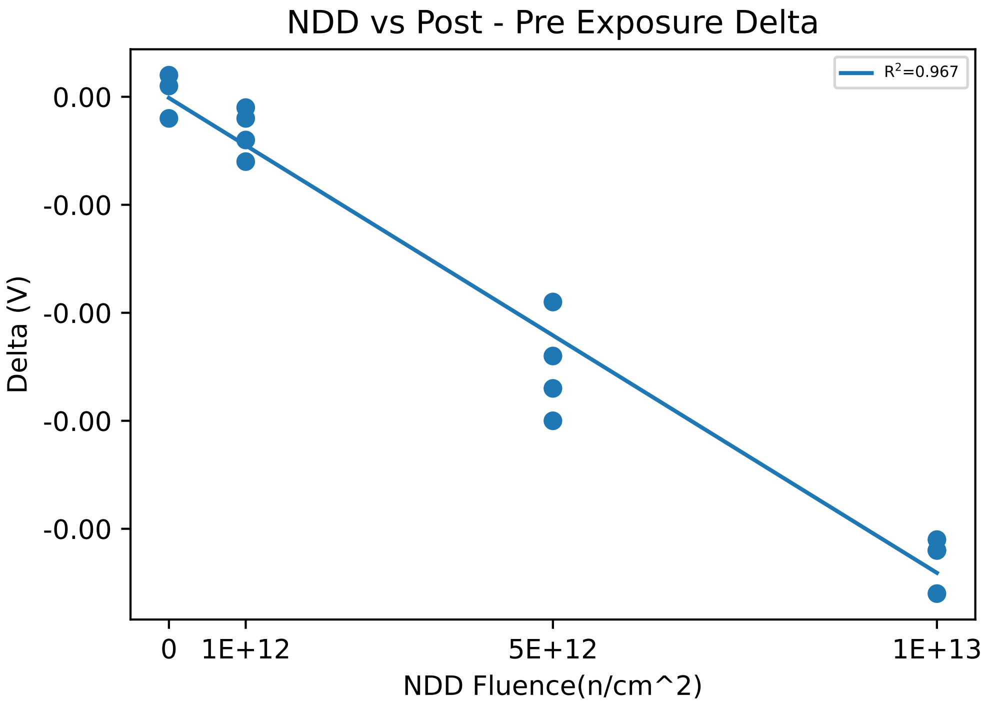
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2246	1.2218	-0.0028
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2234	1.2205	-0.0029
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2216	1.2217	0.0001
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2245	0.0016197	1.2217	1.2235	1.2246	0.0015503	-0.0002	0	0.0001	0.00017321
1e+12	1.2221	1.2235	1.2249	0.0011902	1.2218	1.2231	1.2247	0.0011958	-0.0006	-0.0003	-0.0001	0.00021602
5e+12	1.2234	1.2246	1.226	0.0010878	1.2205	1.222	1.2236	0.0012819	-0.0029	-0.0025	-0.0019	0.00045461
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.2191	1.2207	0.0011325	-0.0046	-0.004275	-0.0041	0.00023629

Device Test: 21.39 VOLTAGE|VREF/VREF/14/14/0/1000/5/500kHz//@V_REFCAP


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

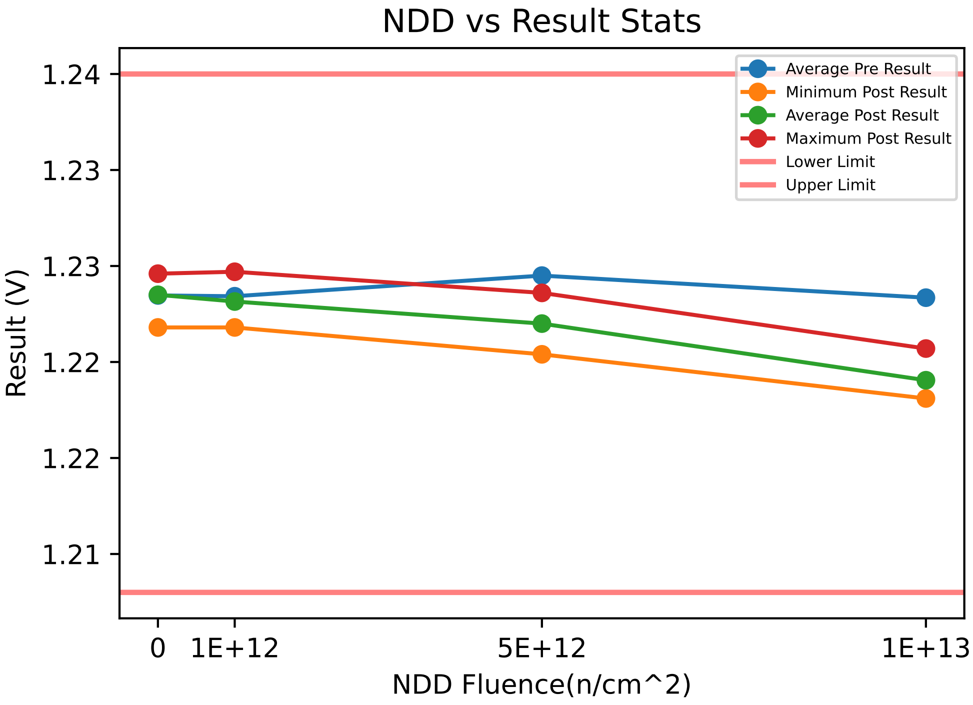
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

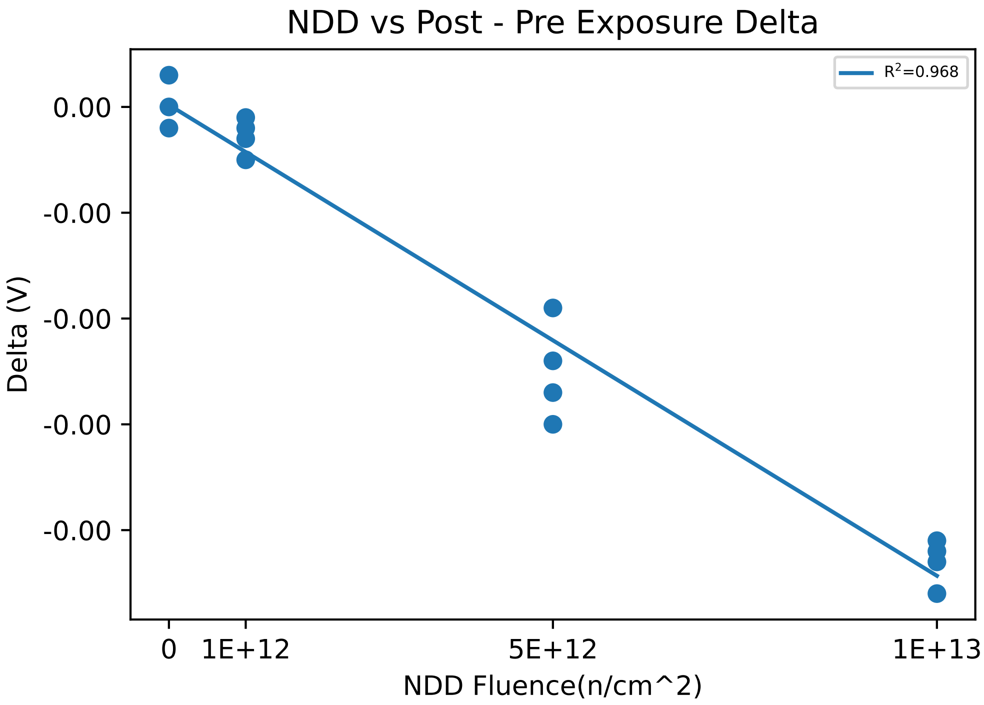
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.223	-0.0001
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2222	1.2218	-0.0004
4	1e+12	NDD	1.225	1.2248	-0.0002
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2205	-0.003
9	1e+13	NDD	1.2224	1.2182	-0.0042
10	1e+13	NDD	1.2227	1.2186	-0.0041
11	1e+13	NDD	1.2231	1.2189	-0.0042
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2222	1.2235	1.225	0.0011815	1.2218	1.2232	1.2248	0.0012329	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2235	1.2246	1.226	0.0010532	1.2205	1.2221	1.2236	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2224	1.2234	1.2254	0.0013638	1.2182	1.2191	1.2208	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.41 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/1MHz//@V_REFCAP





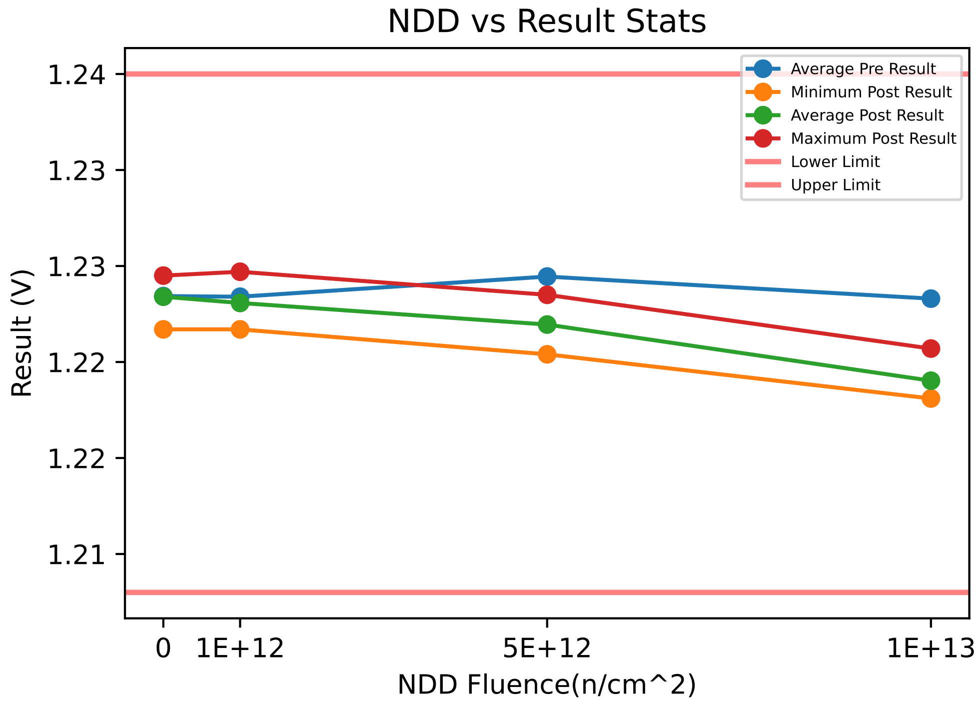
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

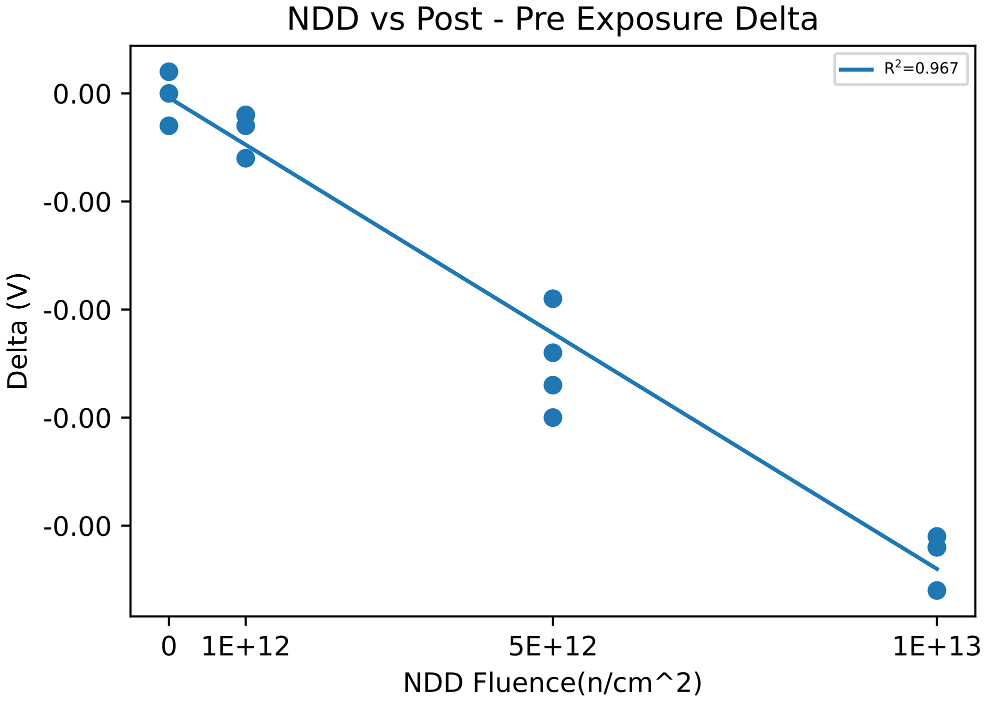
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2218	0.0003
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2246	1.2246	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2235	1.2246	0.0017098	1.2218	1.2235	1.2246	0.0014933	-0.0002	3.3333e-05	0.0003	0.00025166
1e+12	1.2221	1.2234	1.2249	0.0011815	1.2218	1.2231	1.2247	0.0011958	-0.0005	-0.000275	-0.0001	0.00017078
5e+12	1.2234	1.2245	1.226	0.0010985	1.2204	1.222	1.2236	0.0013166	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2224	1.2233	1.2253	0.0013229	1.2181	1.219	1.2207	0.0011475	-0.0046	-0.0043	-0.0041	0.00021602

Device Test: 21.43 VOLTAGE|VREF/VREF/5/5/0/1000/5/1MHz//@V_REFCAP





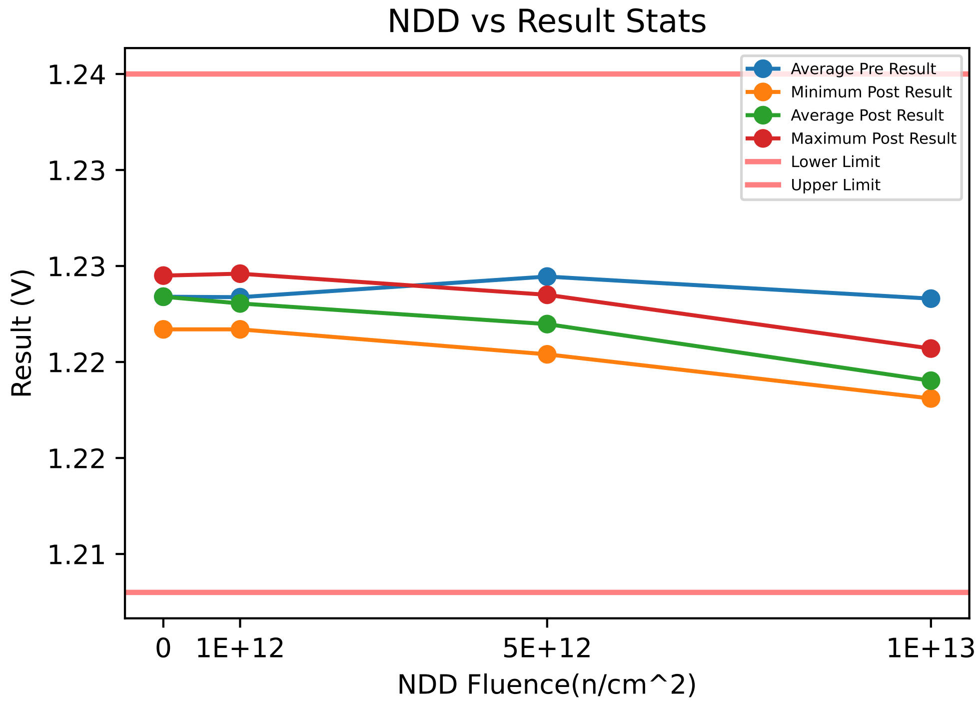
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

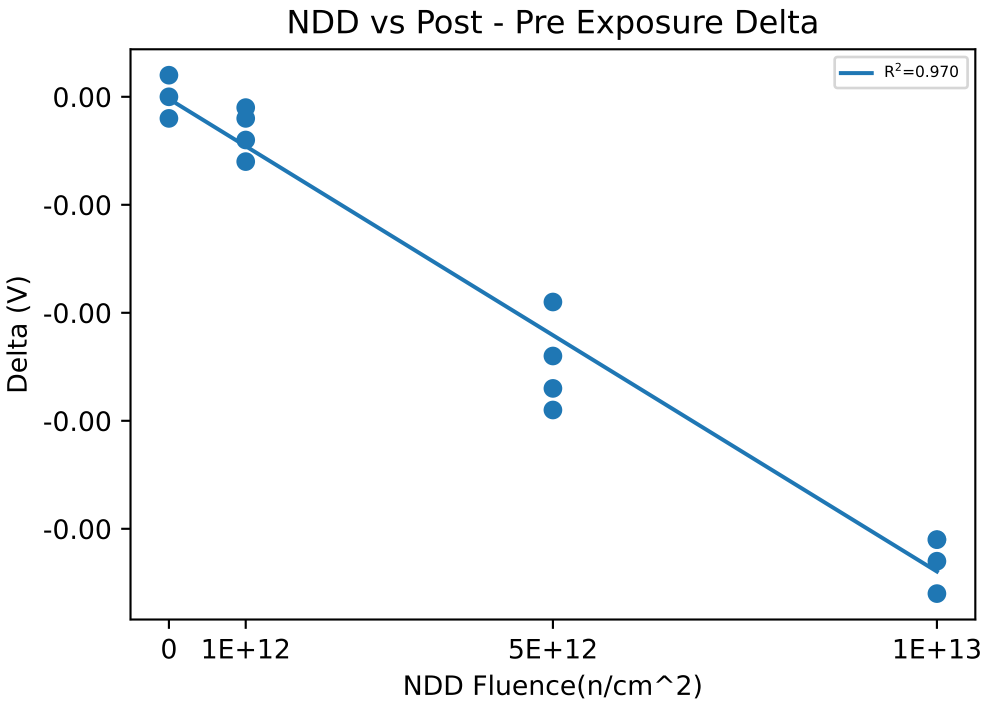
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2228	-0.0002
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.222	1.2217	-0.0003
4	1e+12	NDD	1.2249	1.2247	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.224	1.2221	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.223	1.2188	-0.0042
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2243	1.224	-0.0003
15	0	CORRELATION	1.2245	1.2245	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016773	1.2217	1.2234	1.2245	0.0014933	-0.0003	-3.3333e-05	0.0002	0.00025166
1e+12	1.222	1.2234	1.2249	0.0012193	1.2217	1.2231	1.2247	0.0012393	-0.0006	-0.000325	-0.0002	0.0001893
5e+12	1.2234	1.2245	1.2259	0.0010661	1.2204	1.222	1.2235	0.0012715	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2223	1.2233	1.2253	0.0013638	1.2181	1.219	1.2207	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.45 VOLTAGE|VREF/VREF/12/12/0/1000/5/1MHz//@V_REFCAP





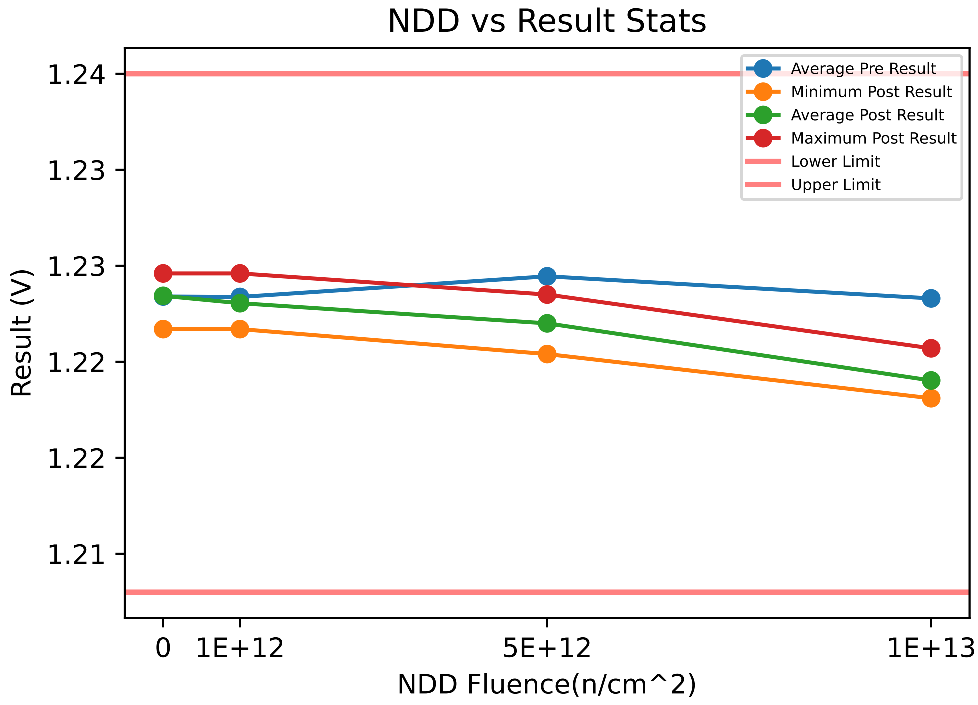
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

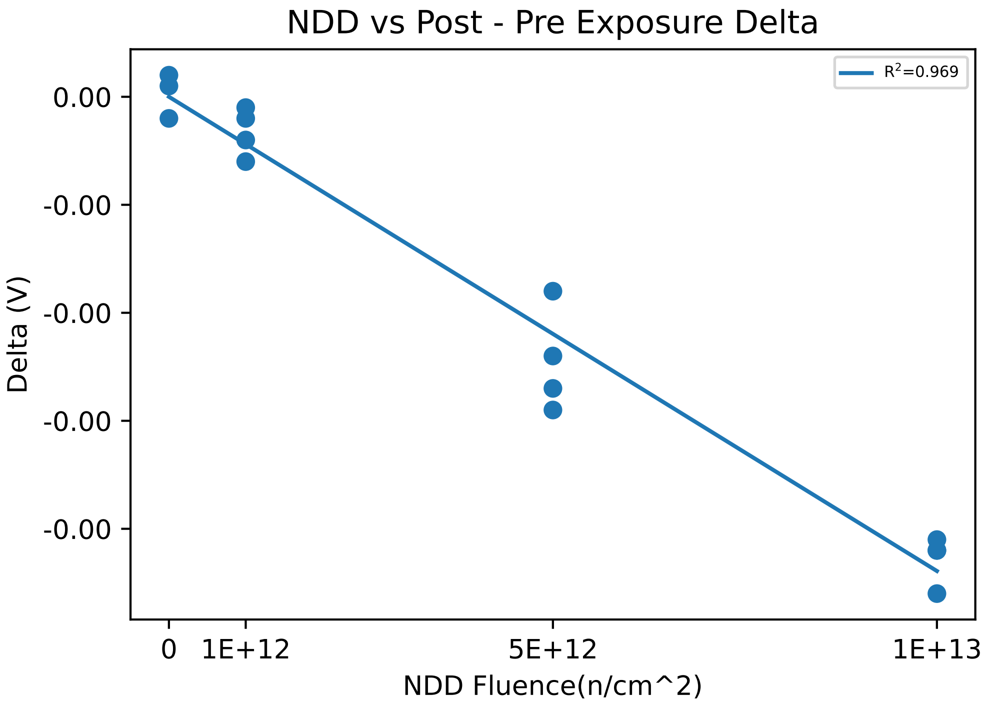
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2229	1.2228	-0.0001
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2248	1.2246	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2233	1.2204	-0.0029
9	1e+13	NDD	1.2224	1.2181	-0.0043
10	1e+13	NDD	1.2226	1.2185	-0.0041
11	1e+13	NDD	1.2229	1.2188	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2242	1.224	-0.0002
15	0	CORRELATION	1.2245	1.2245	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016523	1.2217	1.2234	1.2245	0.0014933	-0.0002	0	0.0002	0.0002
1e+12	1.2221	1.2234	1.2248	0.0011529	1.2217	1.223	1.2246	0.0011958	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2233	1.2245	1.2259	0.0010878	1.2204	1.222	1.2235	0.0012764	-0.0029	-0.002475	-0.0019	0.00043493
1e+13	1.2224	1.2233	1.2253	0.0013491	1.2181	1.219	1.2207	0.0011529	-0.0046	-0.004275	-0.0041	0.00023629

Device Test: 21.47 VOLTAGE|VREF/VREF/14/14/0/1000/5/1MHz//@V_REFCAP


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

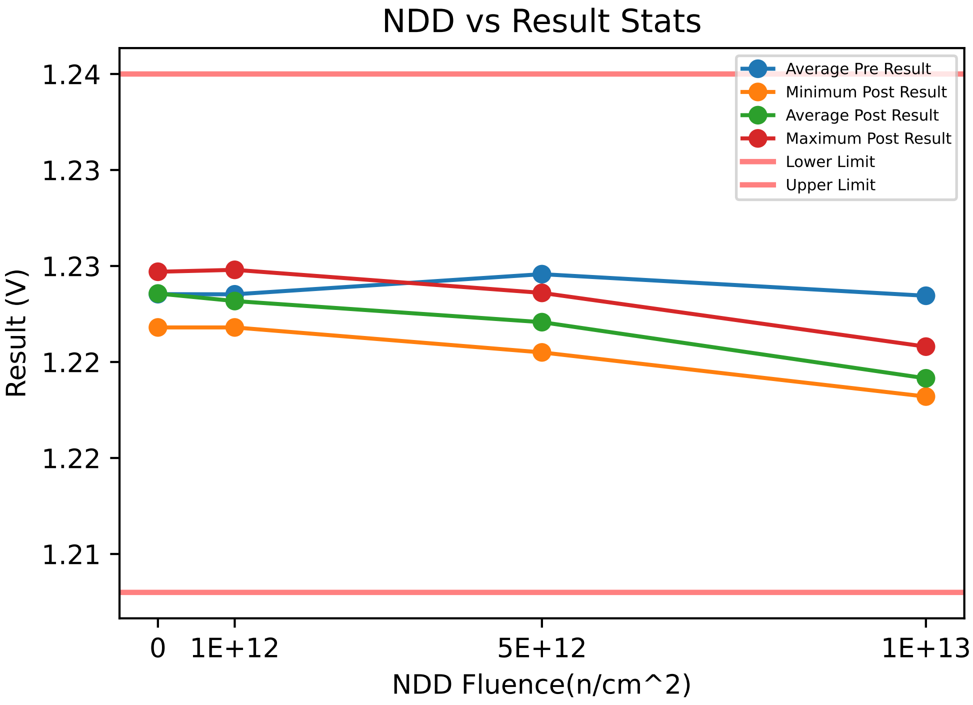
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

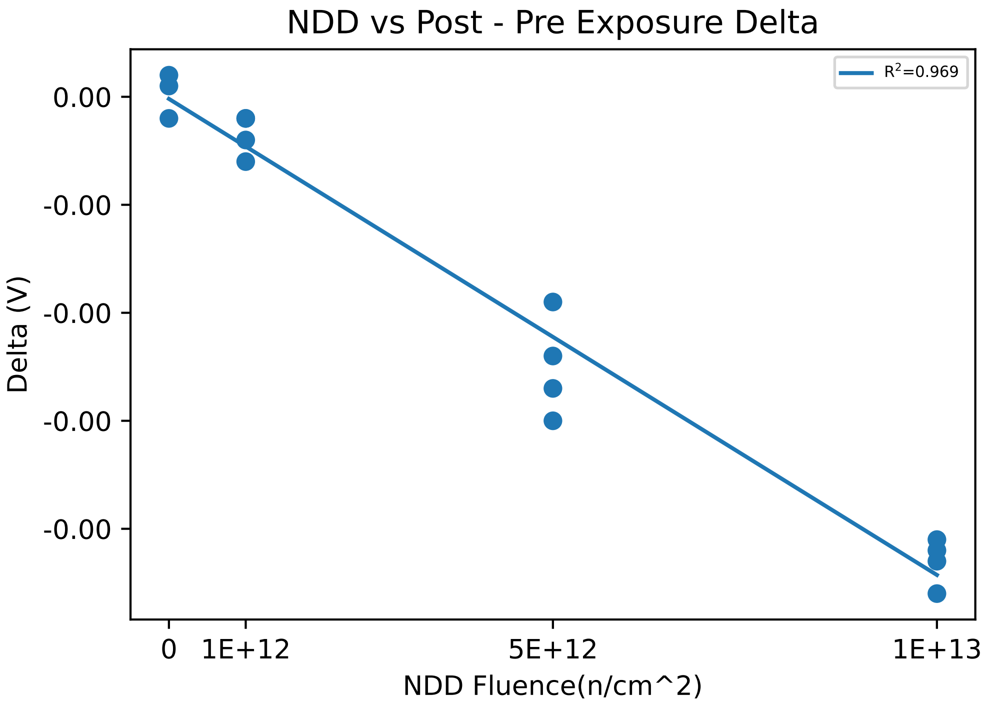
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2229	1.2228	-0.0001
2	1e+12	NDD	1.2237	1.2231	-0.0006
3	1e+12	NDD	1.2221	1.2217	-0.0004
4	1e+12	NDD	1.2248	1.2246	-0.0002
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2235	-0.0024
7	5e+12	NDD	1.2241	1.2223	-0.0018
8	5e+12	NDD	1.2233	1.2204	-0.0029
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.2229	1.2188	-0.0041
12	1e+13	NDD	1.2253	1.2207	-0.0046
13	0	CORRELATION	1.2215	1.2217	0.0002
14	0	CORRELATION	1.2242	1.224	-0.0002
15	0	CORRELATION	1.2245	1.2246	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2234	1.2245	0.0016523	1.2217	1.2234	1.2246	0.0015308	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2221	1.2234	1.2248	0.0011529	1.2217	1.223	1.2246	0.0011958	-0.0006	-0.000325	-0.0001	0.00022174
5e+12	1.2233	1.2245	1.2259	0.0010878	1.2204	1.222	1.2235	0.0012832	-0.0029	-0.00245	-0.0018	0.00047958
1e+13	1.2223	1.2233	1.2253	0.0013565	1.2181	1.219	1.2207	0.0011529	-0.0046	-0.004275	-0.0041	0.00022174

Device Test: 21.5 VOLTAGE|VREF/VREF/12/12/0/0/5/100kHz//@V_REFCAP





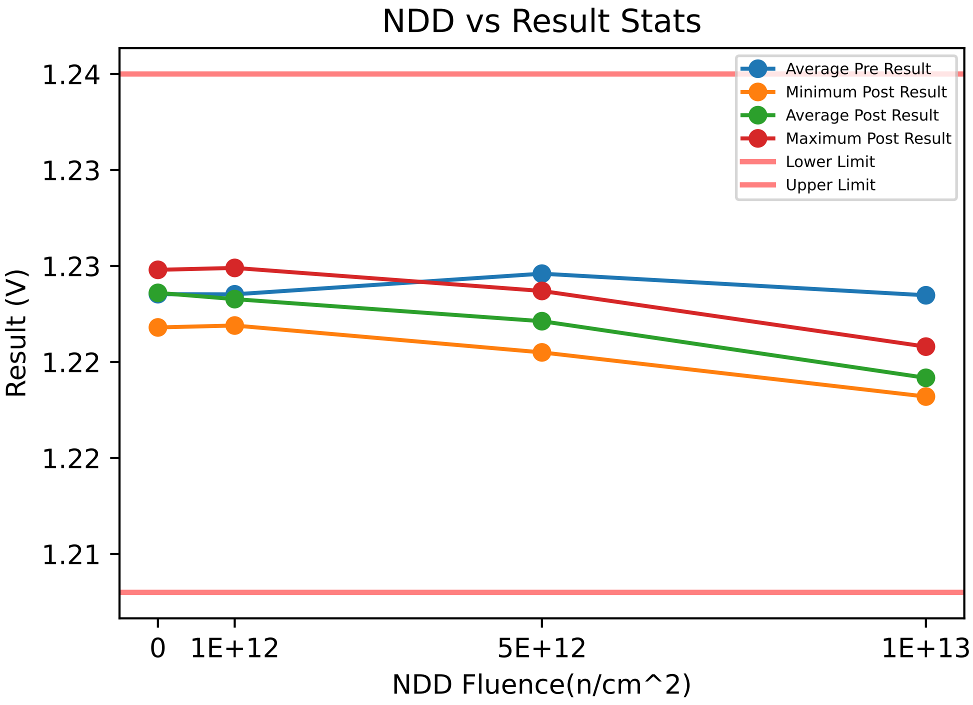
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

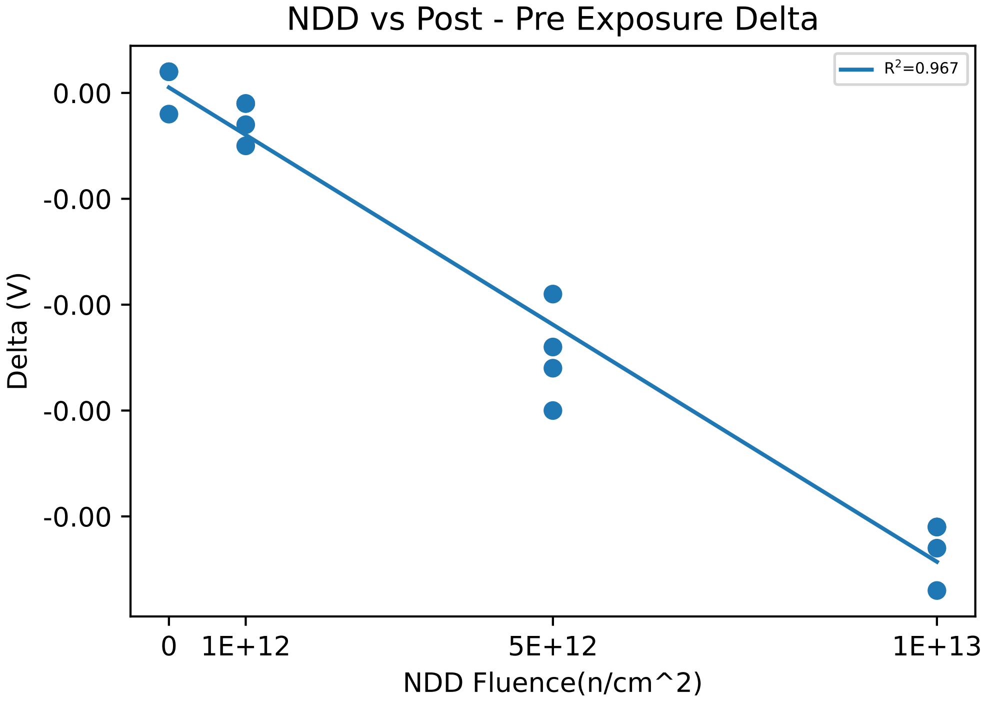
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.2229	-0.0002
2	1e+12	NDD	1.2238	1.2232	-0.0006
3	1e+12	NDD	1.2222	1.2218	-0.0004
4	1e+12	NDD	1.225	1.2248	-0.0002
5	5e+12	NDD	1.2246	1.2219	-0.0027
6	5e+12	NDD	1.226	1.2236	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2205	-0.003
9	1e+13	NDD	1.2225	1.2182	-0.0043
10	1e+13	NDD	1.2228	1.2186	-0.0042
11	1e+13	NDD	1.2231	1.219	-0.0041
12	1e+13	NDD	1.2254	1.2208	-0.0046
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2247	0.0015503	-0.0002	3.3333e-05	0.0002	0.00020817
1e+12	1.2222	1.2235	1.225	0.0011815	1.2218	1.2232	1.2248	0.0012393	-0.0006	-0.00035	-0.0002	0.00019149
5e+12	1.2235	1.2246	1.226	0.0010532	1.2205	1.2221	1.2236	0.0012764	-0.003	-0.0025	-0.0019	0.00046904
1e+13	1.2225	1.2235	1.2254	0.0013229	1.2182	1.2191	1.2208	0.0011475	-0.0046	-0.0043	-0.0041	0.00021602

Device Test: 21.7 VOLTAGE|VREF/VREF/14/14/0/0/5/100kHz//@V_REFCAP





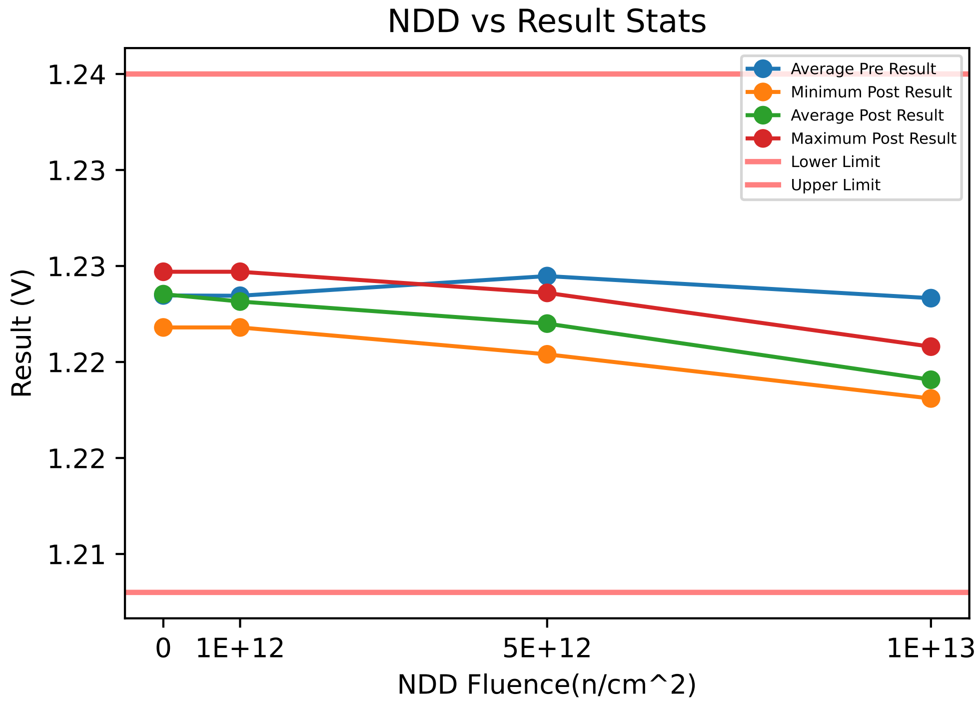
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

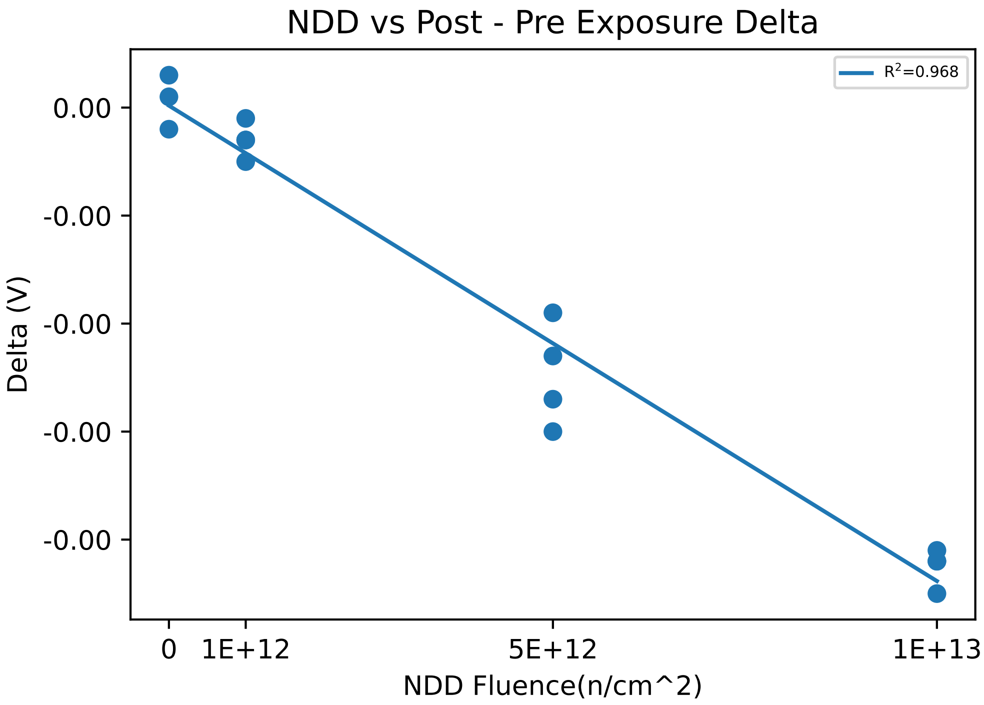
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.2231	1.223	-0.0001
2	1e+12	NDD	1.2238	1.2233	-0.0005
3	1e+12	NDD	1.2222	1.2219	-0.0003
4	1e+12	NDD	1.225	1.2249	-0.0001
5	5e+12	NDD	1.2246	1.222	-0.0026
6	5e+12	NDD	1.2261	1.2237	-0.0024
7	5e+12	NDD	1.2242	1.2223	-0.0019
8	5e+12	NDD	1.2235	1.2205	-0.003
9	1e+13	NDD	1.2225	1.2182	-0.0043
10	1e+13	NDD	1.2228	1.2187	-0.0041
11	1e+13	NDD	1.2231	1.219	-0.0041
12	1e+13	NDD	1.2255	1.2208	-0.0047
13	0	CORRELATION	1.2216	1.2218	0.0002
14	0	CORRELATION	1.2244	1.2242	-0.0002
15	0	CORRELATION	1.2246	1.2248	0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2216	1.2235	1.2246	0.0016773	1.2218	1.2236	1.2248	0.0015875	-0.0002	6.6667e-05	0.0002	0.00023094
1e+12	1.2222	1.2235	1.225	0.0011815	1.2219	1.2233	1.2249	0.0012393	-0.0005	-0.00025	-0.0001	0.00019149
5e+12	1.2235	1.2246	1.2261	0.0010985	1.2205	1.2221	1.2237	0.0013124	-0.003	-0.002475	-0.0019	0.00045735
1e+13	1.2225	1.2235	1.2255	0.001372	1.2182	1.2192	1.2208	0.0011325	-0.0047	-0.0043	-0.0041	0.00028284

Device Test: 21.9 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/500kHz//@V_REFCAP





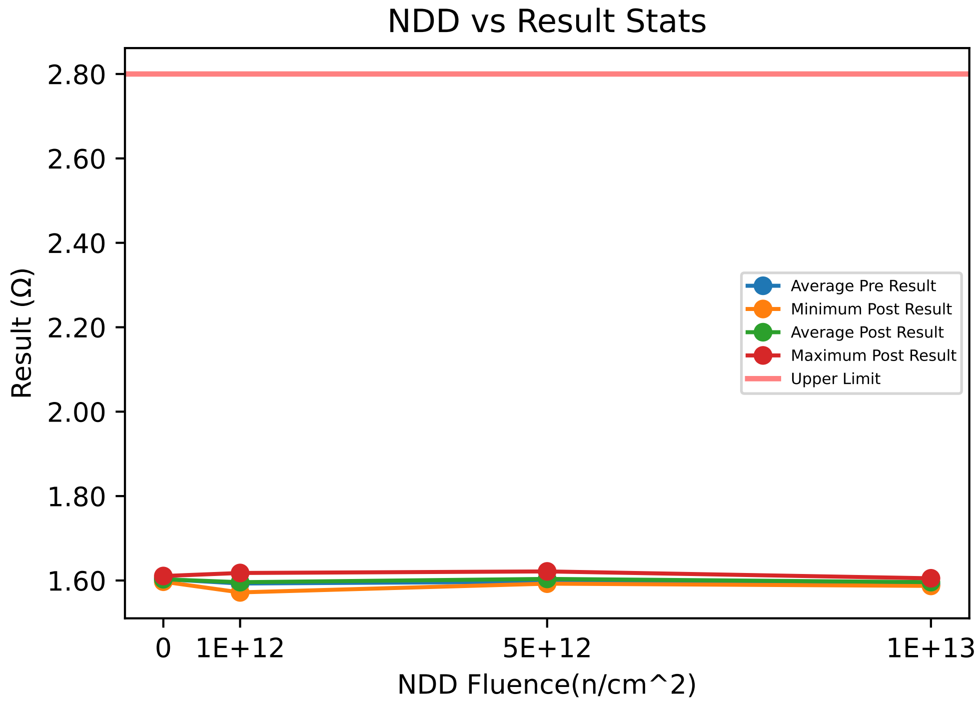
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

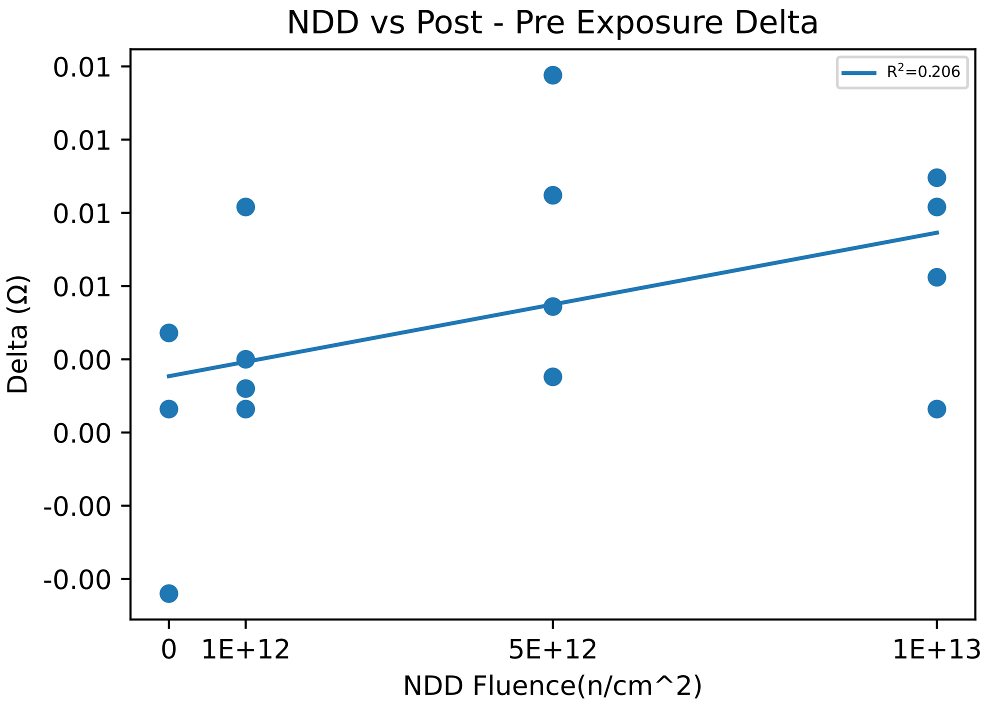
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.223	1.2229	-0.0001
2	1e+12	NDD	1.2237	1.2232	-0.0005
3	1e+12	NDD	1.2221	1.2218	-0.0003
4	1e+12	NDD	1.225	1.2247	-0.0003
5	5e+12	NDD	1.2245	1.2218	-0.0027
6	5e+12	NDD	1.2259	1.2236	-0.0023
7	5e+12	NDD	1.2241	1.2222	-0.0019
8	5e+12	NDD	1.2234	1.2204	-0.003
9	1e+13	NDD	1.2223	1.2181	-0.0042
10	1e+13	NDD	1.2227	1.2185	-0.0042
11	1e+13	NDD	1.223	1.2189	-0.0041
12	1e+13	NDD	1.2253	1.2208	-0.0045
13	0	CORRELATION	1.2215	1.2218	0.0003
14	0	CORRELATION	1.2243	1.2241	-0.0002
15	0	CORRELATION	1.2246	1.2247	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2215	1.2235	1.2246	0.0017098	1.2218	1.2235	1.2247	0.0015308	-0.0002	6.6667e-05	0.0003	0.00025166
1e+12	1.2221	1.2235	1.225	0.0012234	1.2218	1.2231	1.2247	0.0011958	-0.0005	-0.0003	-0.0001	0.0001633
5e+12	1.2234	1.2245	1.2259	0.0010532	1.2204	1.222	1.2236	0.0013166	-0.003	-0.002475	-0.0019	0.00047871
1e+13	1.2223	1.2233	1.2253	0.0013475	1.2181	1.2191	1.2208	0.0011955	-0.0045	-0.00425	-0.0041	0.00017321

Device Test: 23.10 LEVEL|LS_RDSON/OUTL/12/12/100/0/5/500kHz//@ROL





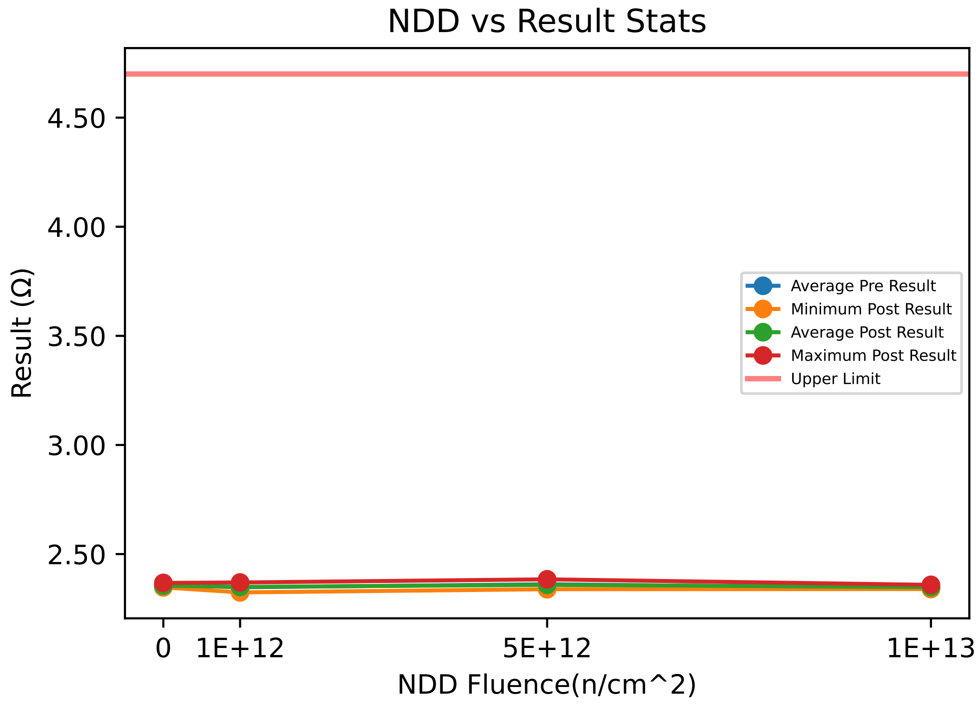
Test Results (Upper Limit = 2.8 (Ω))

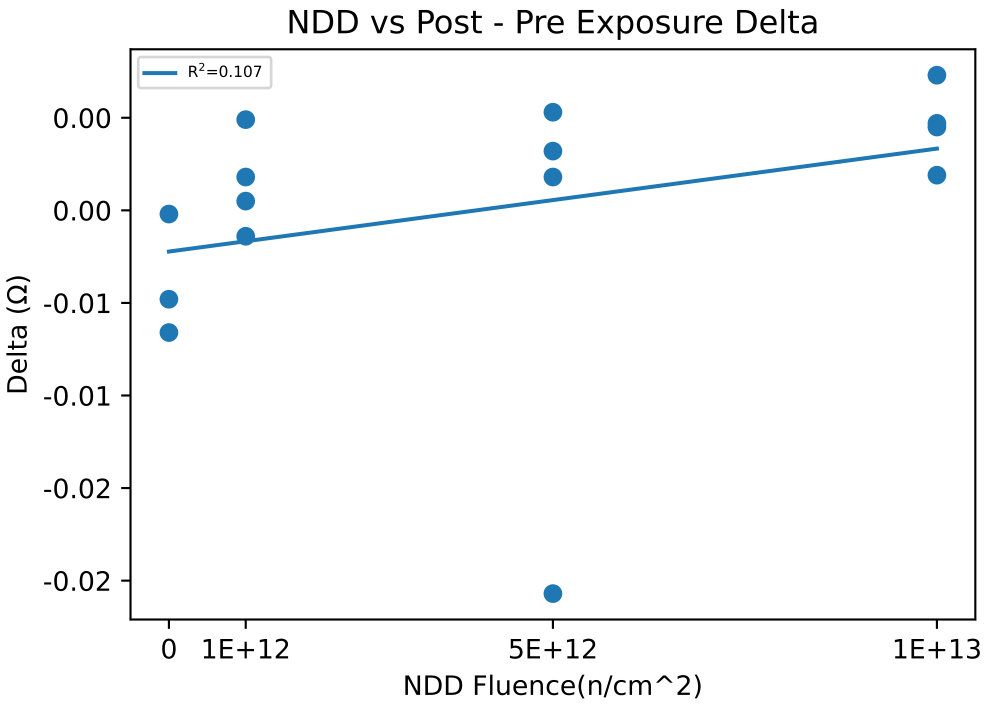
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5693	1.5718	0.0025
2	1e+12	NDD	1.6101	1.6178	0.0077
3	1e+12	NDD	1.5953	1.5961	0.0008
4	1e+12	NDD	1.5967	1.5982	0.0015
5	5e+12	NDD	1.5885	1.5966	0.0081
6	5e+12	NDD	1.5882	1.5925	0.0043
7	5e+12	NDD	1.6196	1.6215	0.0019
8	5e+12	NDD	1.5922	1.6044	0.0122
9	1e+13	NDD	1.5795	1.5872	0.0077
10	1e+13	NDD	1.6029	1.6037	0.0008
11	1e+13	NDD	1.5965	1.6052	0.0087
12	1e+13	NDD	1.5829	1.5882	0.0053
13	0	CORRELATION	1.6065	1.601	-0.0055
14	0	CORRELATION	1.6072	1.6106	0.0034
15	0	CORRELATION	1.5963	1.5971	0.0008

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5963	1.6033	1.6072	0.0061011	1.5971	1.6029	1.6106	0.0069477	-0.0055	-0.00043333	0.0034	0.0045764
1e+12	1.5693	1.5928	1.6101	0.017059	1.5718	1.596	1.6178	0.018848	0.0008	0.003125	0.0077	0.0031288
5e+12	1.5882	1.5971	1.6196	0.015093	1.5925	1.6038	1.6215	0.012821	0.0019	0.006625	0.0122	0.0045088
1e+13	1.5795	1.5904	1.6029	0.011083	1.5872	1.5961	1.6052	0.0096986	0.0008	0.005625	0.0087	0.0035189

Device Test: 23.11 LEVEL|HS_RDSON/OUTH/14/14/100/0/5/500kHz//@ROH





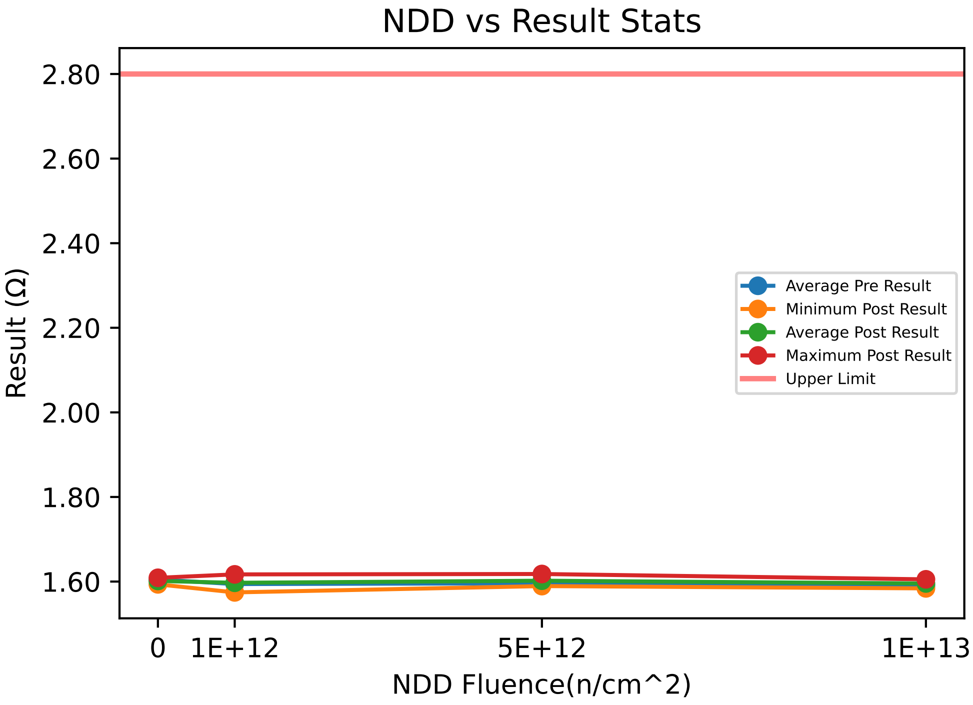
Test Results (Upper Limit = 4.7 (Ω))

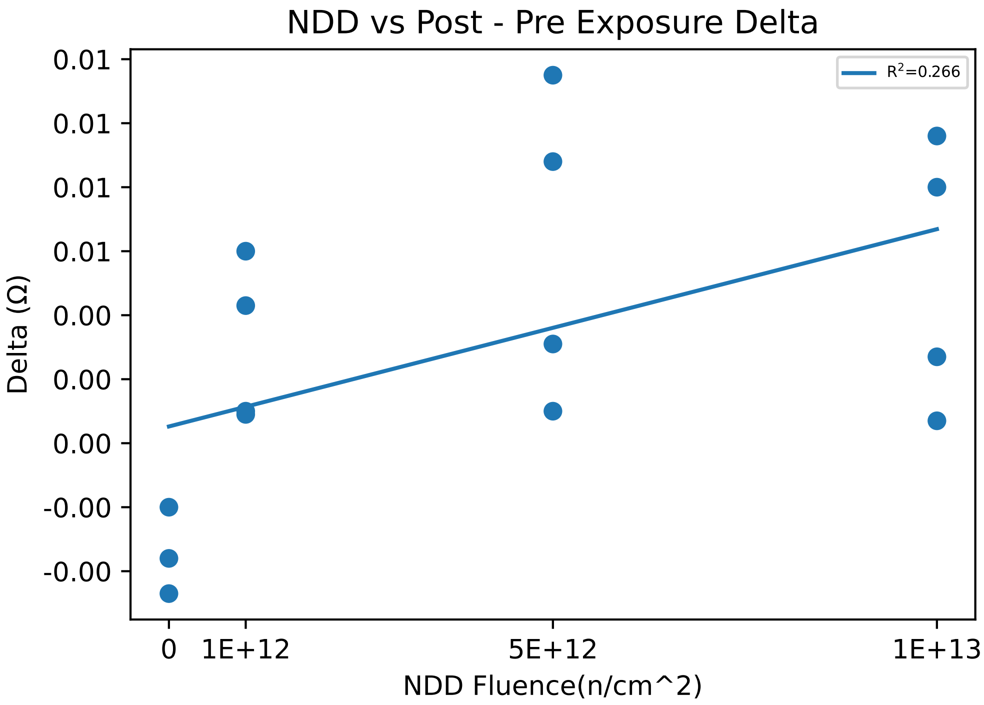
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3195	2.3244	0.0049
2	1e+12	NDD	2.3631	2.3649	0.0018
3	1e+12	NDD	2.3693	2.3698	0.0005
4	1e+12	NDD	2.3398	2.3384	-0.0014
5	5e+12	NDD	2.3597	2.339	-0.0207
6	5e+12	NDD	2.3414	2.3432	0.0018
7	5e+12	NDD	2.3662	2.3694	0.0032
8	5e+12	NDD	2.379	2.3843	0.0053
9	1e+13	NDD	2.3351	2.3398	0.0047
10	1e+13	NDD	2.3448	2.3493	0.0045
11	1e+13	NDD	2.357	2.3589	0.0019
12	1e+13	NDD	2.3388	2.3461	0.0073
13	0	CORRELATION	2.3476	2.3474	-0.0002
14	0	CORRELATION	2.3571	2.3505	-0.0066
15	0	CORRELATION	2.3726	2.3678	-0.0048

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3476	2.3591	2.3726	0.012619	2.3474	2.3552	2.3678	0.010993	-0.0066	-0.0038667	-0.0002	0.0033005
1e+12	2.3195	2.3479	2.3693	0.022812	2.3244	2.3494	2.3698	0.021621	-0.0014	0.00145	0.0049	0.0026489
5e+12	2.3414	2.3616	2.379	0.015659	2.339	2.359	2.3843	0.021586	-0.0207	-0.0026	0.0053	0.012152
1e+13	2.3351	2.3439	2.357	0.0095894	2.3398	2.3485	2.3589	0.0079634	0.0019	0.0046	0.0073	0.0022061

Device Test: 23.12 LEVEL|LS_RDSON/OUTL/14/14/100/0/5/500kHz//@ROL





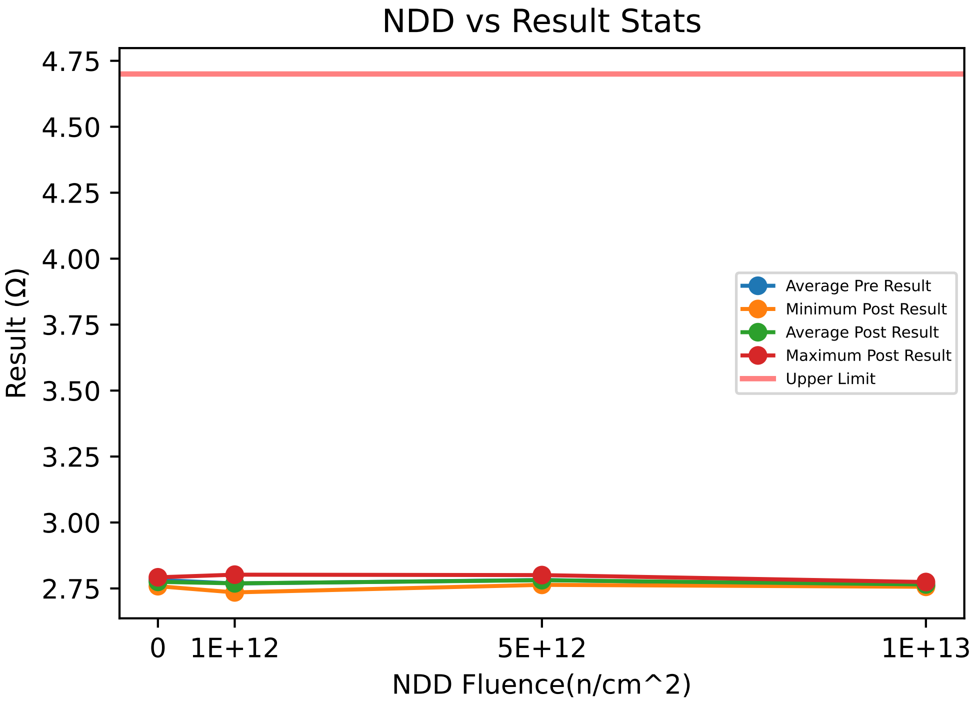
Test Results (Upper Limit = 2.8 (Ω))

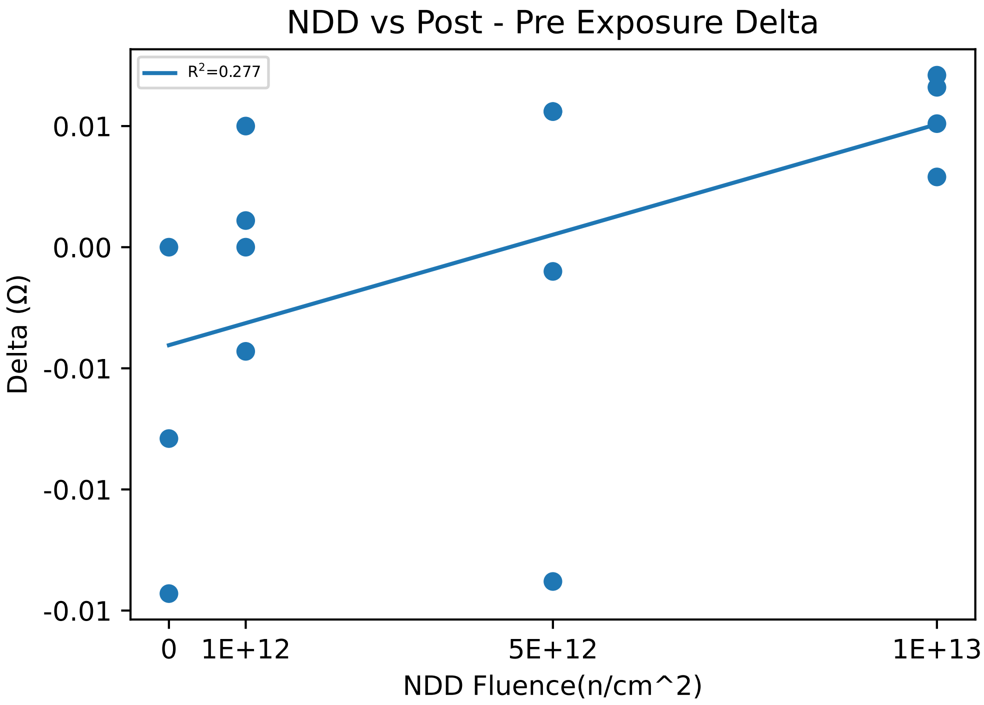
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5734	1.5744	0.001
2	1e+12	NDD	1.611	1.617	0.006
3	1e+12	NDD	1.5927	1.597	0.0043
4	1e+12	NDD	1.5992	1.6001	0.0009
5	5e+12	NDD	1.5876	1.5964	0.0088
6	5e+12	NDD	1.5862	1.5893	0.0031
7	5e+12	NDD	1.6169	1.6179	0.001
8	5e+12	NDD	1.5931	1.6046	0.0115
9	1e+13	NDD	1.5812	1.5839	0.0027
10	1e+13	NDD	1.6039	1.6046	0.0007
11	1e+13	NDD	1.5973	1.6053	0.008
12	1e+13	NDD	1.5786	1.5882	0.0096
13	0	CORRELATION	1.6056	1.602	-0.0036
14	0	CORRELATION	1.6109	1.6089	-0.002
15	0	CORRELATION	1.5981	1.5934	-0.0047

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5981	1.6049	1.6109	0.0064314	1.5934	1.6014	1.6089	0.0077655	-0.0047	-0.0034333	-0.002	0.0013577
1e+12	1.5734	1.5941	1.611	0.015728	1.5744	1.5971	1.617	0.017515	0.0009	0.00305	0.006	0.0025226
5e+12	1.5862	1.5959	1.6169	0.014281	1.5893	1.602	1.6179	0.012277	0.001	0.0061	0.0115	0.0048806
1e+13	1.5786	1.5902	1.6039	0.012297	1.5839	1.5955	1.6053	0.011056	0.0007	0.00525	0.0096	0.0042304

Device Test: 23.5 LEVEL|HS_RDSON/OUTH/4.5/4.5/100/0/4.5/500kHz//@ROH





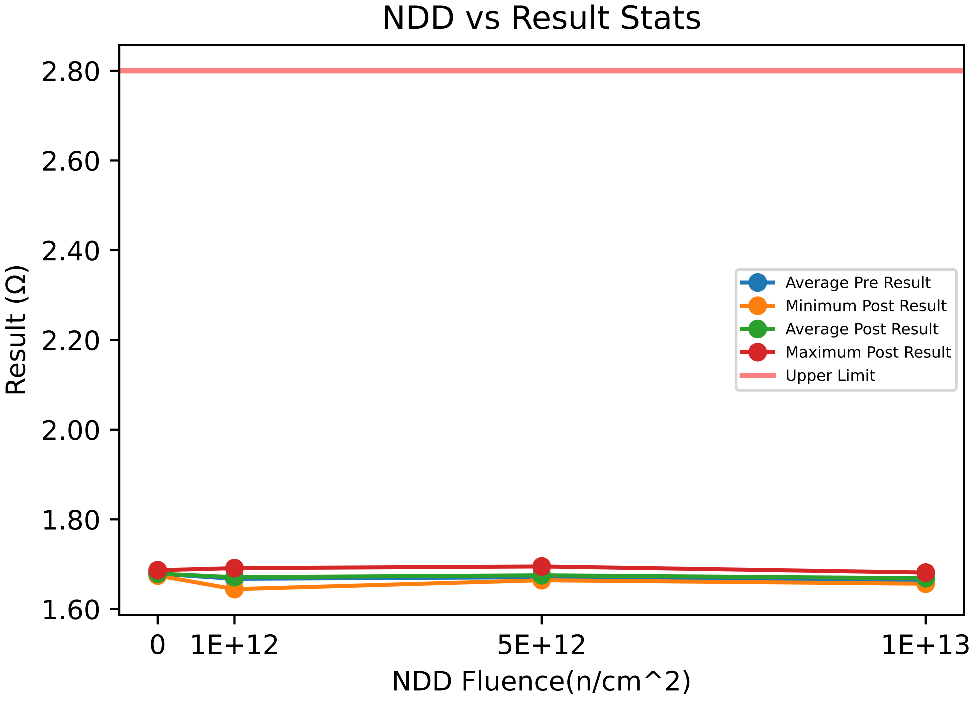
Test Results (Upper Limit = 4.7 (Ω))

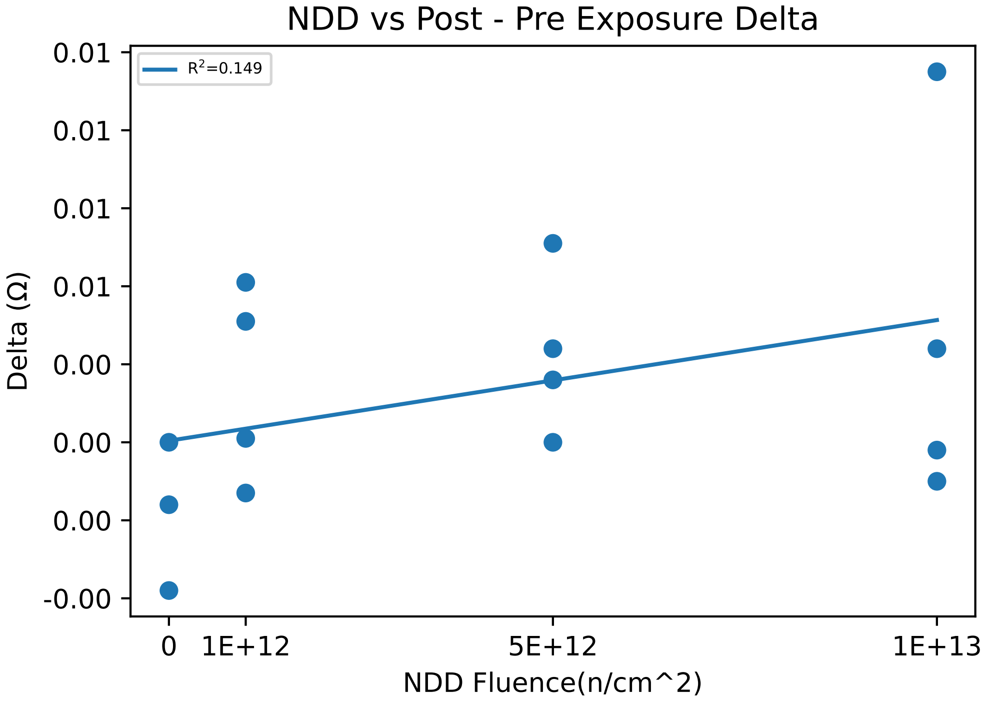
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.73	2.735	0.005
2	1e+12	NDD	2.7907	2.7864	-0.0043
3	1e+12	NDD	2.8011	2.8022	0.0011
4	1e+12	NDD	2.7534	2.7534	0
5	5e+12	NDD	2.7926	2.7788	-0.0138
6	5e+12	NDD	2.758	2.7636	0.0056
7	5e+12	NDD	2.795	2.8006	0.0056
8	5e+12	NDD	2.7827	2.7817	-0.001
9	1e+13	NDD	2.7586	2.7652	0.0066
10	1e+13	NDD	2.7594	2.7645	0.0051
11	1e+13	NDD	2.7714	2.7743	0.0029
12	1e+13	NDD	2.7491	2.7562	0.0071
13	0	CORRELATION	2.7664	2.7585	-0.0079
14	0	CORRELATION	2.7885	2.7742	-0.0143
15	0	CORRELATION	2.7922	2.7922	0

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7664	2.7824	2.7922	0.013951	2.7585	2.775	2.7922	0.016863	-0.0143	-0.0074	0	0.0071631
1e+12	2.73	2.7688	2.8011	0.032992	2.735	2.7692	2.8022	0.030573	-0.0043	0.00045	0.005	0.0038249
5e+12	2.758	2.7821	2.795	0.01691	2.7636	2.7812	2.8006	0.015189	-0.0138	-0.0009	0.0056	0.0091455
1e+13	2.7491	2.7596	2.7714	0.0091383	2.7562	2.7651	2.7743	0.0073984	0.0029	0.005425	0.0071	0.0018857

Device Test: 23.6 LEVEL|LS_RDSON/OUTL/4.5/4.5/100/0/4.5/500kHz//@ROL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

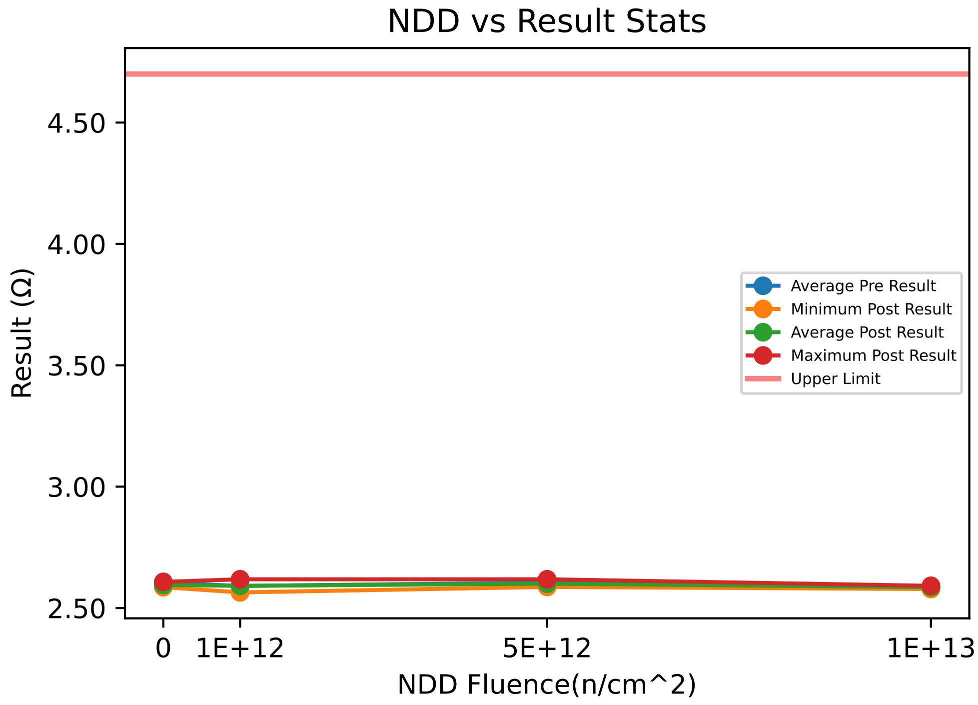
Test Results (Upper Limit = 2.8 (Ω))

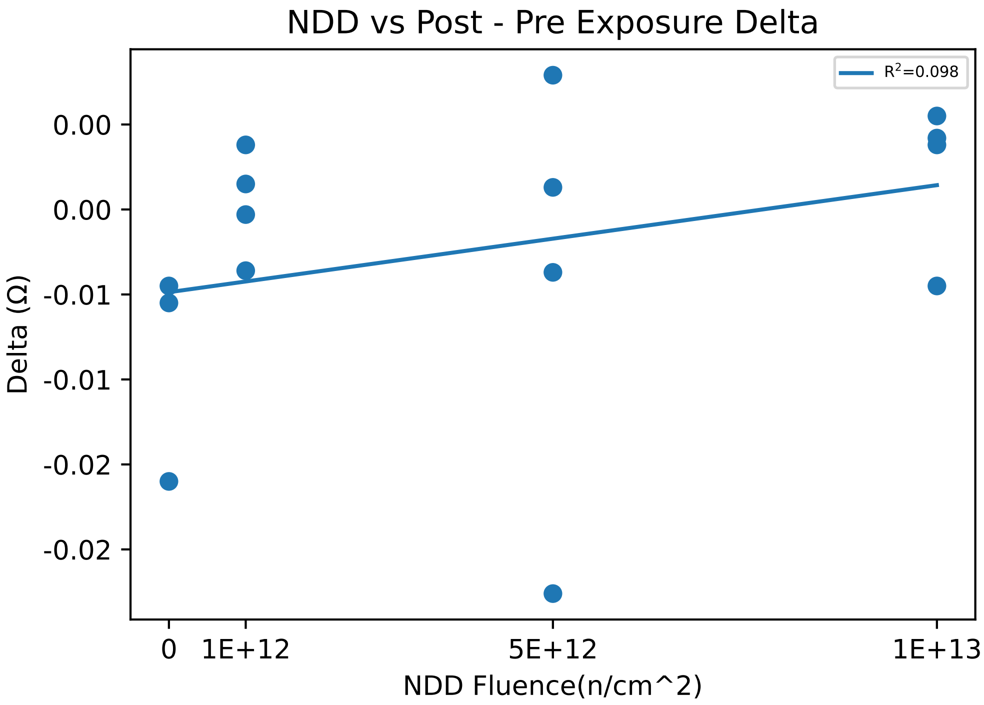
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.6424	1.6445	0.0021
2	1e+12	NDD	1.6862	1.6913	0.0051
3	1e+12	NDD	1.6663	1.6724	0.0061
4	1e+12	NDD	1.6756	1.6763	0.0007
5	5e+12	NDD	1.6658	1.6702	0.0044
6	5e+12	NDD	1.6608	1.6644	0.0036
7	5e+12	NDD	1.6931	1.6951	0.002
8	5e+12	NDD	1.6648	1.6719	0.0071
9	1e+13	NDD	1.6556	1.6566	0.001
10	1e+13	NDD	1.6755	1.6773	0.0018
11	1e+13	NDD	1.67	1.6815	0.0115
12	1e+13	NDD	1.6555	1.6599	0.0044
13	0	CORRELATION	1.6765	1.6747	-0.0018
14	0	CORRELATION	1.6863	1.6867	0.0004
15	0	CORRELATION	1.674	1.676	0.002

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.674	1.6789	1.6863	0.006501	1.6747	1.6791	1.6867	0.0065851	-0.0018	0.0002	0.002	0.0019079
1e+12	1.6424	1.6676	1.6862	0.018679	1.6445	1.6711	1.6913	0.019531	0.0007	0.0035	0.0061	0.0025245
5e+12	1.6608	1.6711	1.6931	0.014808	1.6644	1.6754	1.6951	0.01352	0.002	0.004275	0.0071	0.0021313
1e+13	1.6555	1.6642	1.6755	0.010181	1.6566	1.6688	1.6815	0.012404	0.001	0.004675	0.0115	0.0047759

Device Test: 23.7 LEVEL|HS_RDSON/OUTH/5/5/100/0/5/500kHz//@ROH





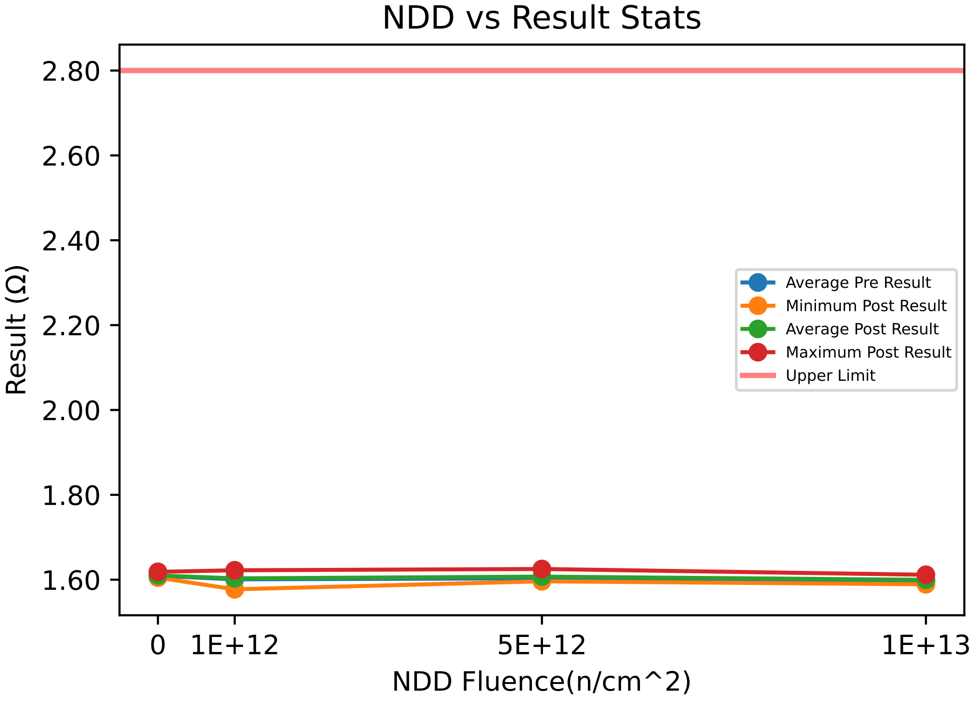
Test Results (Upper Limit = 4.7 (Ω))

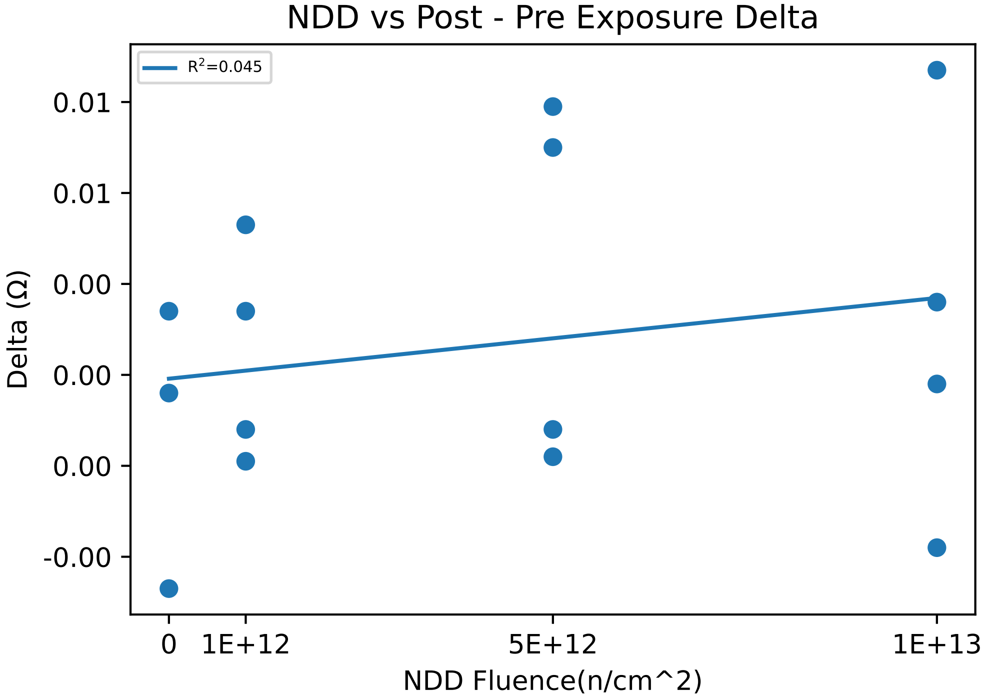
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.5606	2.5644	0.0038
2	1e+12	NDD	2.6072	2.6036	-0.0036
3	1e+12	NDD	2.6187	2.6184	-0.0003
4	1e+12	NDD	2.5777	2.5792	0.0015
5	5e+12	NDD	2.616	2.5934	-0.0226
6	5e+12	NDD	2.5857	2.587	0.0013
7	5e+12	NDD	2.6105	2.6184	0.0079
8	5e+12	NDD	2.6059	2.6022	-0.0037
9	1e+13	NDD	2.5808	2.5863	0.0055
10	1e+13	NDD	2.5842	2.588	0.0038
11	1e+13	NDD	2.596	2.5915	-0.0045
12	1e+13	NDD	2.574	2.5782	0.0042
13	0	CORRELATION	2.5905	2.586	-0.0045
14	0	CORRELATION	2.6077	2.5917	-0.016
15	0	CORRELATION	2.6132	2.6077	-0.0055

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5905	2.6038	2.6132	0.011842	2.586	2.5951	2.6077	0.01125	-0.016	-0.0086667	-0.0045	0.0063705
1e+12	2.5606	2.5911	2.6187	0.026651	2.5644	2.5914	2.6184	0.024191	-0.0036	0.00035	0.0038	0.0031225
5e+12	2.5857	2.6045	2.616	0.013212	2.587	2.6002	2.6184	0.01361	-0.0226	-0.004275	0.0079	0.013108
1e+13	2.574	2.5838	2.596	0.009202	2.5782	2.586	2.5915	0.0056326	-0.0045	0.00225	0.0055	0.0045581

Device Test: 23.8 LEVEL|LS_RDSON/OUTL/5/5/100/0/5/500kHz//@ROL





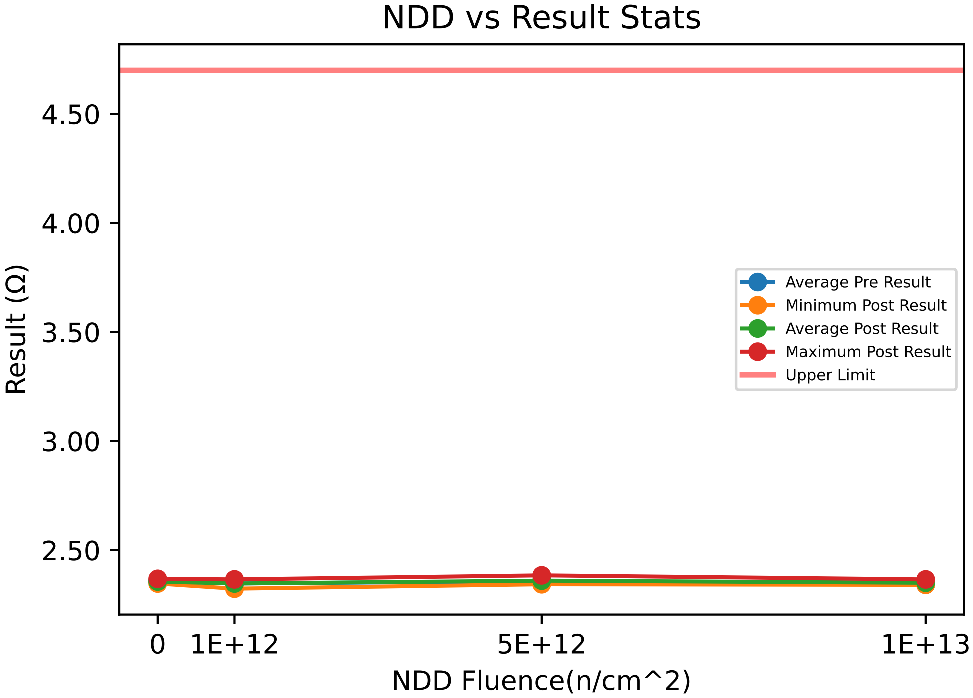
Test Results (Upper Limit = 2.8 (Ω))

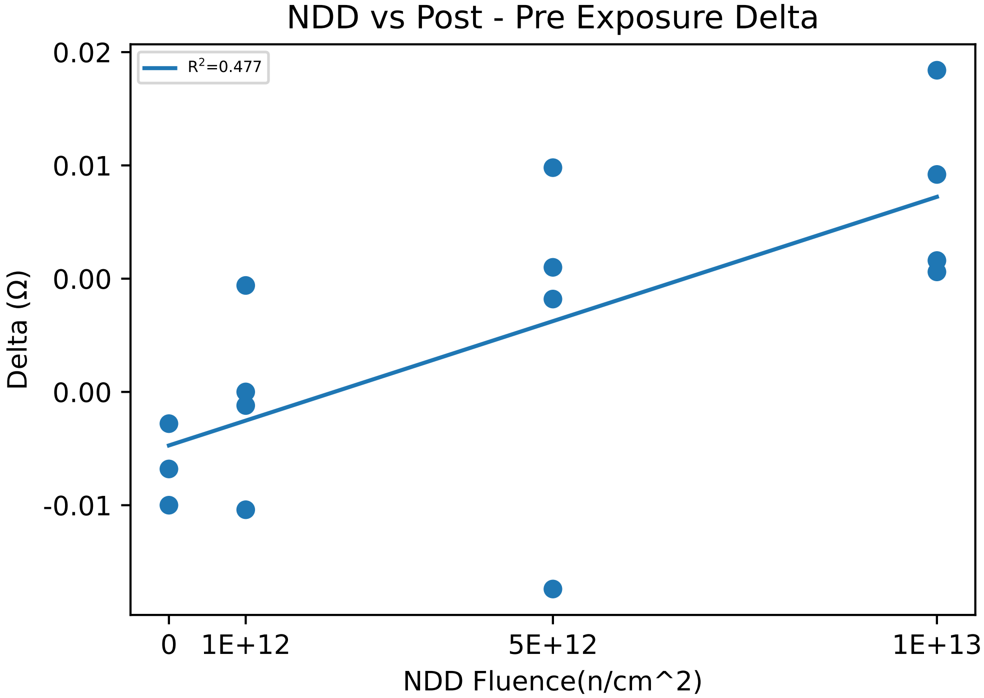
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.5772	1.5773	0.0001
2	1e+12	NDD	1.6188	1.6222	0.0034
3	1e+12	NDD	1.5989	1.6042	0.0053
4	1e+12	NDD	1.6082	1.609	0.0008
5	5e+12	NDD	1.594	1.601	0.007
6	5e+12	NDD	1.5954	1.5962	0.0008
7	5e+12	NDD	1.625	1.6252	0.0002
8	5e+12	NDD	1.5985	1.6064	0.0079
9	1e+13	NDD	1.5872	1.5908	0.0036
10	1e+13	NDD	1.609	1.6072	-0.0018
11	1e+13	NDD	1.6029	1.6116	0.0087
12	1e+13	NDD	1.5873	1.5891	0.0018
13	0	CORRELATION	1.6091	1.6064	-0.0027
14	0	CORRELATION	1.6151	1.6185	0.0034
15	0	CORRELATION	1.6032	1.6048	0.0016

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6032	1.6091	1.6151	0.0059501	1.6048	1.6099	1.6185	0.0074907	-0.0027	0.00076667	0.0034	0.0031342
1e+12	1.5772	1.6008	1.6188	0.017695	1.5773	1.6032	1.6222	0.018854	0.0001	0.0024	0.0053	0.0023986
5e+12	1.594	1.6032	1.625	0.014638	1.5962	1.6072	1.6252	0.012703	0.0002	0.003975	0.0079	0.0040368
1e+13	1.5872	1.5966	1.609	0.01108	1.5891	1.5997	1.6116	0.011393	-0.0018	0.003075	0.0087	0.0043706

Device Test: 23.9 LEVEL|HS_RDSON/OUTH/12/12/100/0/5/500kHz//@ROH





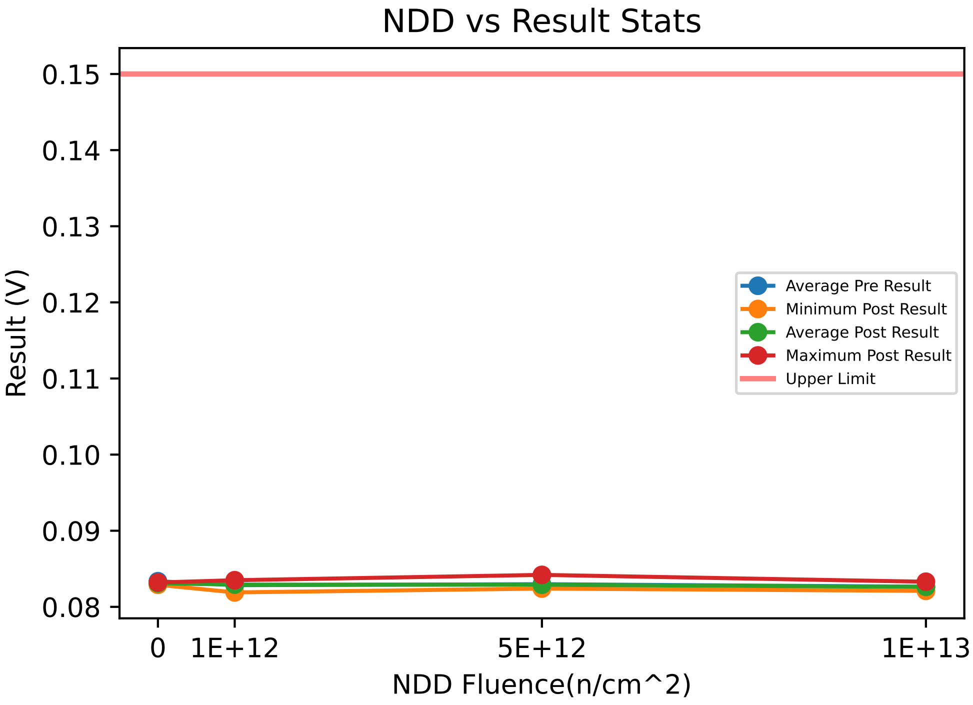
Test Results (Upper Limit = 4.7 (Ω))

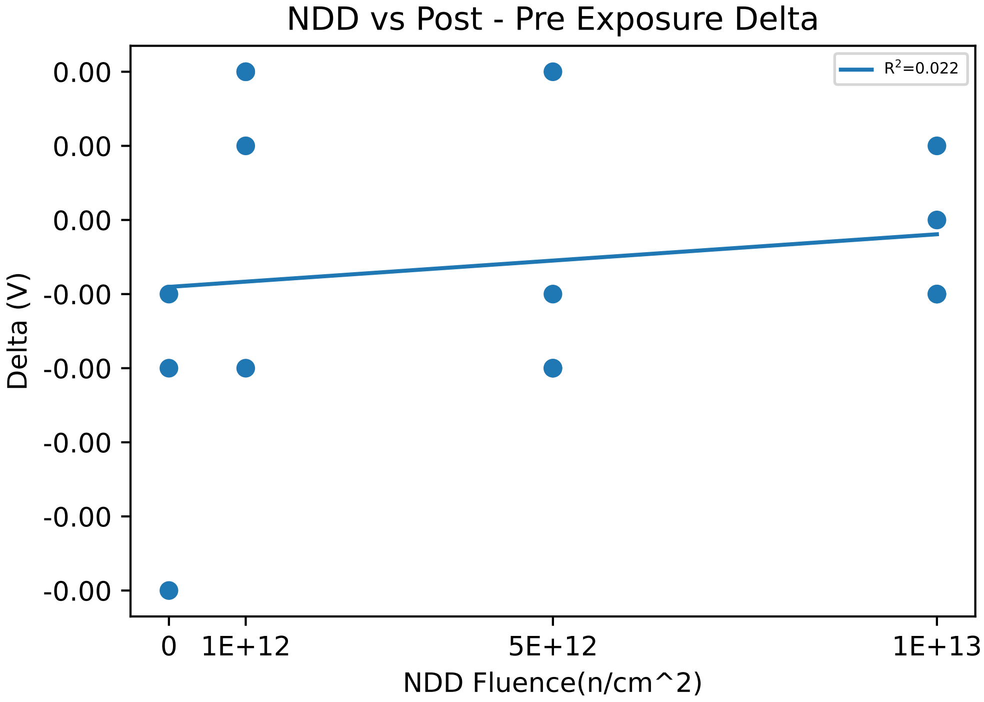
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.3187	2.3234	0.0047
2	1e+12	NDD	2.3628	2.3628	0
3	1e+12	NDD	2.3711	2.3659	-0.0052
4	1e+12	NDD	2.3365	2.3359	-0.0006
5	5e+12	NDD	2.3548	2.3461	-0.0087
6	5e+12	NDD	2.3395	2.3436	0.0041
7	5e+12	NDD	2.3611	2.3666	0.0055
8	5e+12	NDD	2.3745	2.3844	0.0099
9	1e+13	NDD	2.3314	2.341	0.0096
10	1e+13	NDD	2.3441	2.3494	0.0053
11	1e+13	NDD	2.3516	2.3658	0.0142
12	1e+13	NDD	2.3399	2.3457	0.0058
13	0	CORRELATION	2.3504	2.347	-0.0034
14	0	CORRELATION	2.354	2.3526	-0.0014
15	0	CORRELATION	2.3735	2.3685	-0.005

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3504	2.3593	2.3735	0.012429	2.347	2.356	2.3685	0.011154	-0.005	-0.0032667	-0.0014	0.0018037
1e+12	2.3187	2.3473	2.3711	0.024092	2.3234	2.347	2.3659	0.020712	-0.0052	-0.000275	0.0047	0.0040492
5e+12	2.3395	2.3575	2.3745	0.014529	2.3436	2.3602	2.3844	0.019157	-0.0087	0.0027	0.0099	0.0079917
1e+13	2.3314	2.3418	2.3516	0.0084279	2.341	2.3505	2.3658	0.010779	0.0053	0.008725	0.0142	0.0041242

Device Test: 24.1 LEVEL|LOW_LEVEL/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_VOL





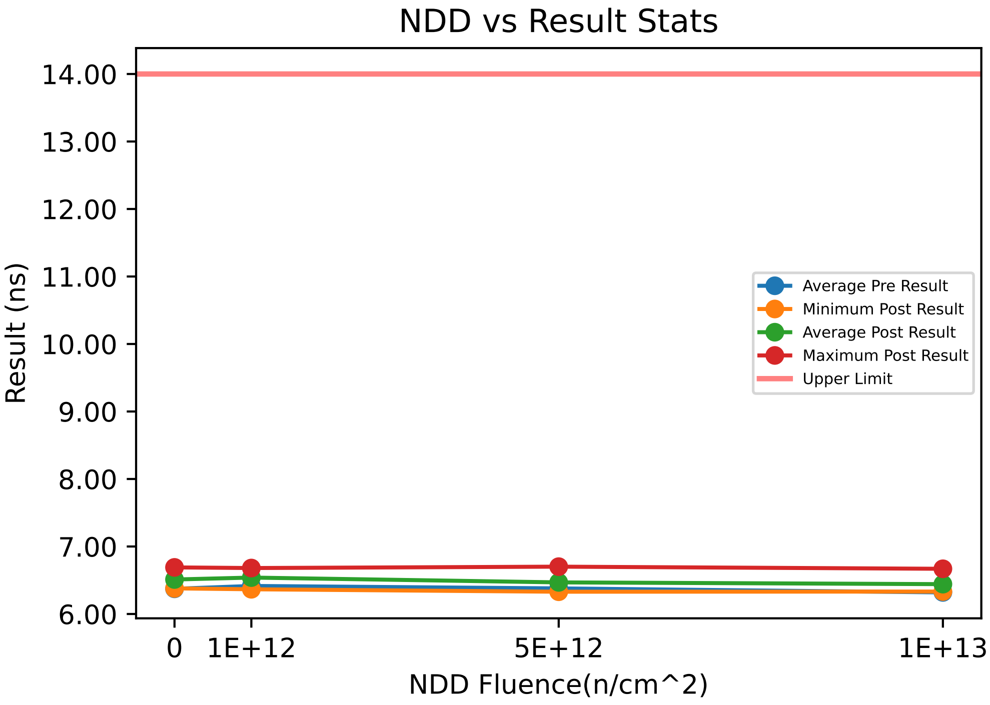
Test Results (Upper Limit = 0.15 (V))

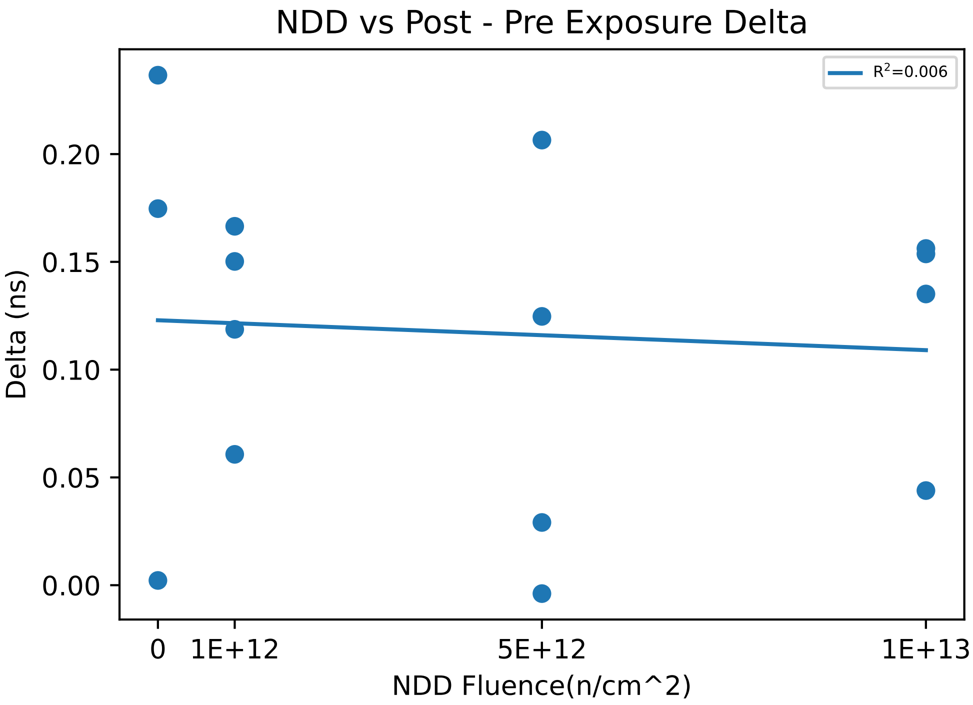
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0817	0.0819	0.0002
2	1e+12	NDD	0.0837	0.0835	-0.0002
3	1e+12	NDD	0.0829	0.083	0.0001
4	1e+12	NDD	0.0831	0.0833	0.0002
5	5e+12	NDD	0.0827	0.0825	-0.0002
6	5e+12	NDD	0.0825	0.0824	-0.0001
7	5e+12	NDD	0.084	0.0842	0.0002
8	5e+12	NDD	0.0827	0.0825	-0.0002
9	1e+13	NDD	0.0822	0.0821	-0.0001
10	1e+13	NDD	0.0832	0.0833	0.0001
11	1e+13	NDD	0.083	0.0829	-0.0001
12	1e+13	NDD	0.0822	0.0822	0
13	0	CORRELATION	0.0833	0.0832	-0.0001
14	0	CORRELATION	0.0837	0.0832	-0.0005
15	0	CORRELATION	0.0831	0.0829	-0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0831	0.083367	0.0837	0.00030551	0.0829	0.0831	0.0832	0.00017321	-0.0005	-0.00026667	-0.0001	0.00020817
1e+12	0.0817	0.08285	0.0837	0.00083865	0.0819	0.082925	0.0835	0.00071356	-0.0002	7.5e-05	0.0002	0.0001893
5e+12	0.0825	0.082975	0.084	0.00068981	0.0824	0.0829	0.0842	0.00086795	-0.0002	-7.5e-05	0.0002	0.0001893
1e+13	0.0822	0.08265	0.0832	0.00052599	0.0821	0.082625	0.0833	0.00057373	-0.0001	-2.5e-05	0.0001	9.5743e-05

Device Test: 24.10 TIMING|OUT_FALL/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_FALL_4P5V





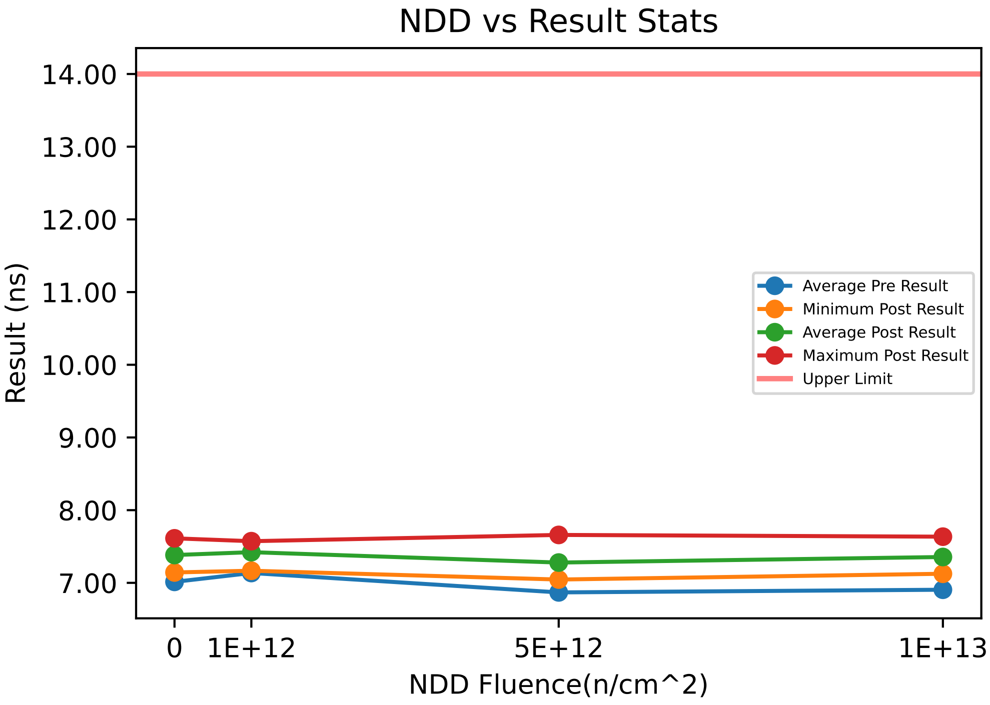
Test Results (Upper Limit = 14.0 (ns))

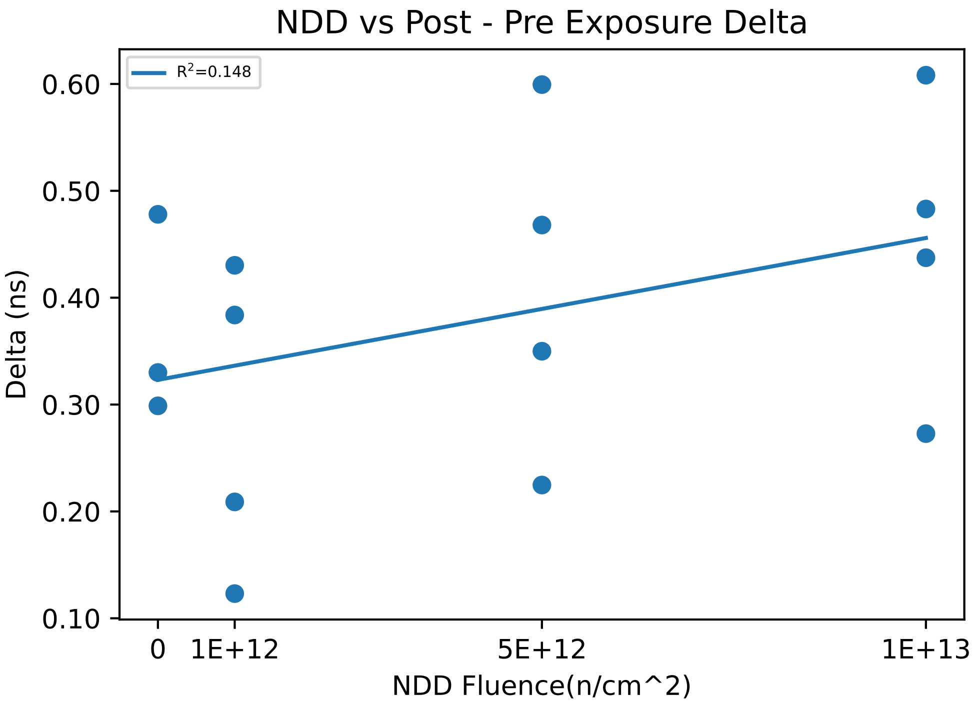
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.4804	6.6469	0.1665
2	1e+12	NDD	6.4034	6.4641	0.0607
3	1e+12	NDD	6.216	6.3662	0.1502
4	1e+12	NDD	6.5621	6.6808	0.1187
5	5e+12	NDD	6.4158	6.4449	0.0291
6	5e+12	NDD	6.1233	6.3298	0.2065
7	5e+12	NDD	6.5765	6.7012	0.1247
8	5e+12	NDD	6.4012	6.3973	-0.0039
9	1e+13	NDD	6.1972	6.3323	0.1351
10	1e+13	NDD	6.5159	6.6696	0.1537
11	1e+13	NDD	6.3781	6.422	0.0439
12	1e+13	NDD	6.1883	6.3445	0.1562
13	0	CORRELATION	6.5156	6.6903	0.1747
14	0	CORRELATION	6.4611	6.4633	0.0022
15	0	CORRELATION	6.1427	6.3793	0.2366

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1427	6.3731	6.5156	0.20141	6.3793	6.511	6.6903	0.16089	0.0022	0.13783	0.2366	0.12147
1e+12	6.216	6.4155	6.5621	0.14793	6.3662	6.5395	6.6808	0.14969	0.0607	0.12402	0.1665	0.046646
5e+12	6.1233	6.3792	6.5765	0.18818	6.3298	6.4683	6.7012	0.16229	-0.0039	0.0891	0.2065	0.095392
1e+13	6.1883	6.3199	6.5159	0.15724	6.3323	6.4421	6.6696	0.15678	0.0439	0.12223	0.1562	0.053058

Device Test: 24.11 TIMING|OUT_RISE/OUTH/5/5/0/1000/5/500kHz//@OUT_RISE_5V





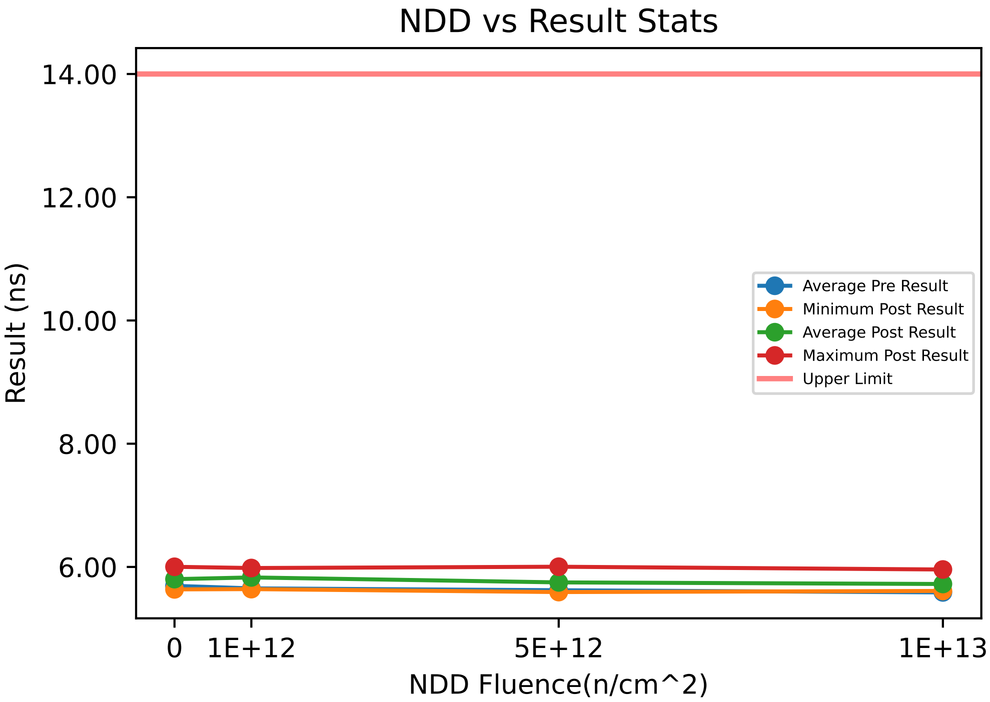
Test Results (Upper Limit = 14.0 (ns))

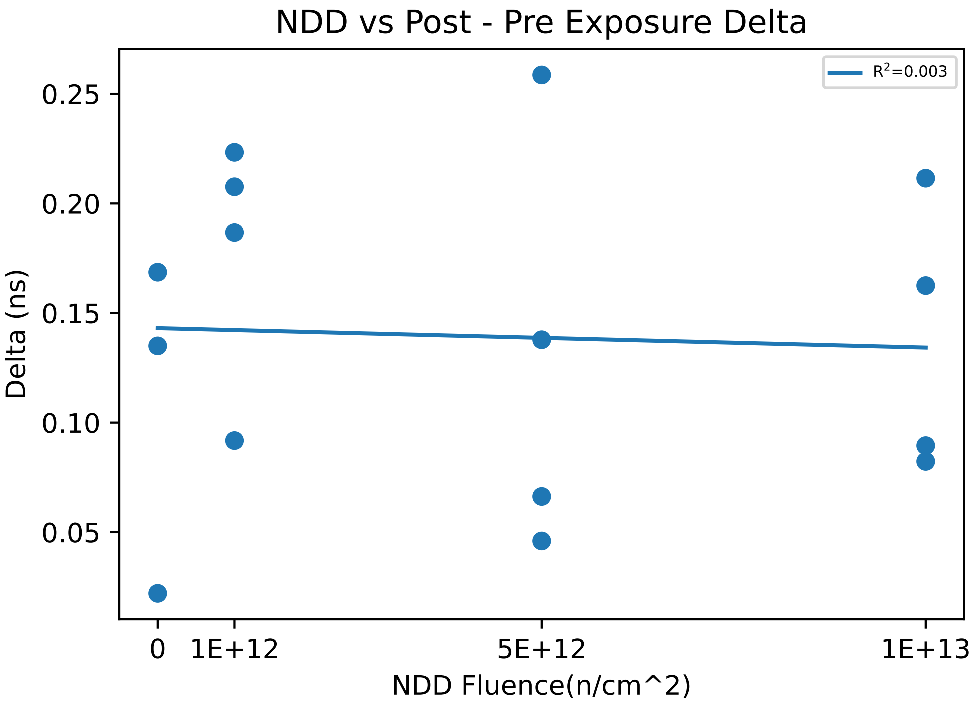
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.1428	7.5731	0.4303
2	1e+12	NDD	7.0438	7.1669	0.1231
3	1e+12	NDD	7.0152	7.399	0.3838
4	1e+12	NDD	7.3401	7.549	0.2089
5	5e+12	NDD	6.6586	7.1266	0.468
6	5e+12	NDD	6.6856	7.285	0.5994
7	5e+12	NDD	7.4346	7.6593	0.2247
8	5e+12	NDD	6.6958	7.0457	0.3499
9	1e+13	NDD	6.7615	7.3697	0.6082
10	1e+13	NDD	7.1523	7.6353	0.483
11	1e+13	NDD	6.8523	7.1251	0.2728
12	1e+13	NDD	6.8549	7.2923	0.4374
13	0	CORRELATION	7.1344	7.6124	0.478
14	0	CORRELATION	6.8131	7.1431	0.33
15	0	CORRELATION	7.0933	7.3921	0.2988

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.8131	7.0136	7.1344	0.17485	7.1431	7.3825	7.6124	0.2348	0.2988	0.36893	0.478	0.095734
1e+12	7.0152	7.1355	7.3401	0.14696	7.1669	7.422	7.5731	0.1867	0.1231	0.28653	0.4303	0.14476
5e+12	6.6586	6.8686	7.4346	0.37763	7.0457	7.2791	7.6593	0.27222	0.2247	0.4105	0.5994	0.1604
1e+13	6.7615	6.9052	7.1523	0.17033	7.1251	7.3556	7.6353	0.21258	0.2728	0.45035	0.6082	0.13865

Device Test: 24.12 TIMING|OUT_FALL/OUTH/5/5/0/1000/5/500kHz//@OUT_FALL_5V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

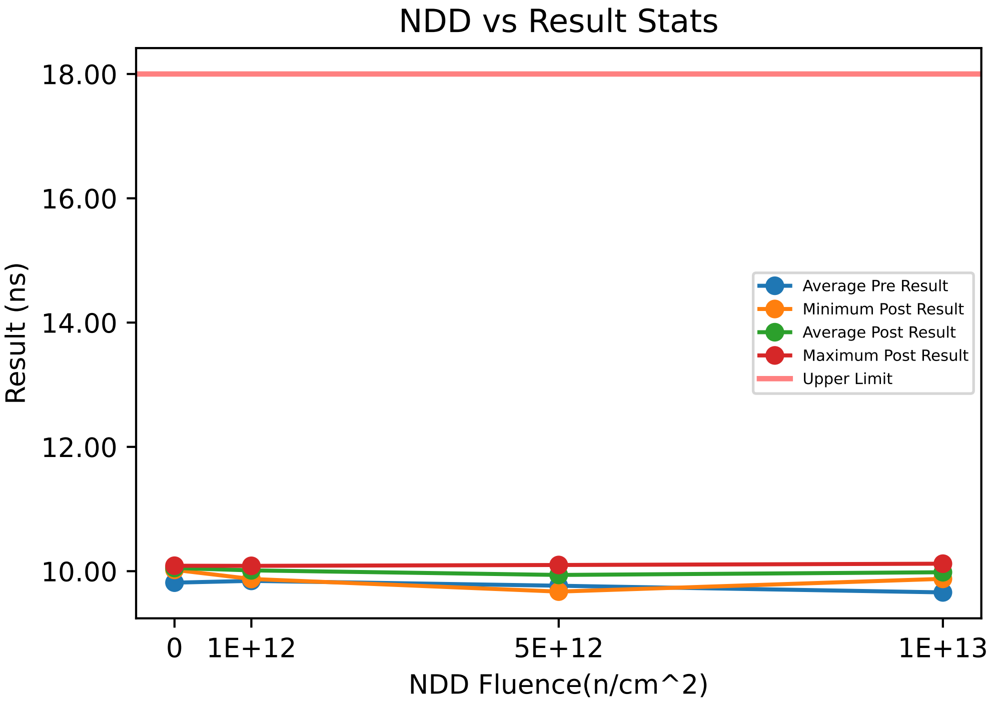
Test Results (Upper Limit = 14.0 (ns))

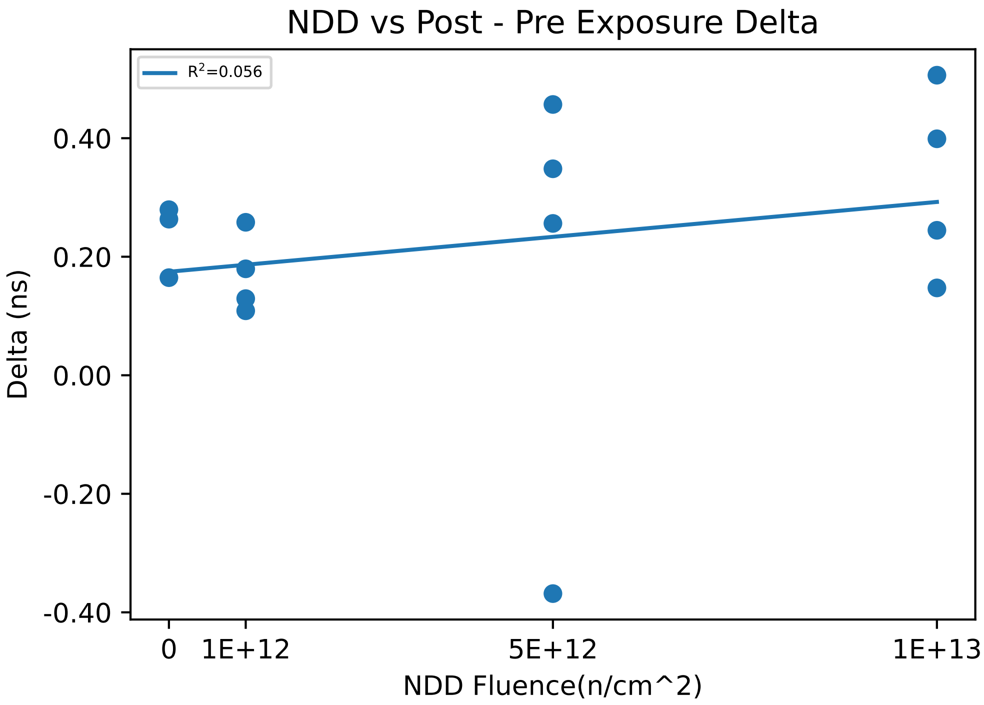
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	5.748	5.9556	0.2076
2	1e+12	NDD	5.6491	5.7409	0.0918
3	1e+12	NDD	5.4169	5.6402	0.2233
4	1e+12	NDD	5.7959	5.9826	0.1867
5	5e+12	NDD	5.6753	5.7213	0.046
6	5e+12	NDD	5.3338	5.5924	0.2586
7	5e+12	NDD	5.8657	6.0035	0.1378
8	5e+12	NDD	5.6139	5.6802	0.0663
9	1e+13	NDD	5.4138	5.6253	0.2115
10	1e+13	NDD	5.8692	5.9587	0.0895
11	1e+13	NDD	5.6166	5.6989	0.0823
12	1e+13	NDD	5.4483	5.6108	0.1625
13	0	CORRELATION	5.8675	6.0025	0.135
14	0	CORRELATION	5.7452	5.7673	0.0221
15	0	CORRELATION	5.4674	5.636	0.1686

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4674	5.6934	5.8675	0.20502	5.636	5.8019	6.0025	0.18569	0.0221	0.10857	0.1686	0.076744
1e+12	5.4169	5.6525	5.7959	0.16853	5.6402	5.8298	5.9826	0.16636	0.0918	0.17735	0.2233	0.058971
5e+12	5.3338	5.6222	5.8657	0.22012	5.5924	5.7493	6.0035	0.17776	0.046	0.12717	0.2586	0.096057
1e+13	5.4138	5.587	5.8692	0.20797	5.6108	5.7234	5.9587	0.16152	0.0823	0.13645	0.2115	0.061773

Device Test: 24.13 TIMING|OUT_RISE/OUTH/12/12/0/1000/5/500kHz//@OUT_RISE_12V





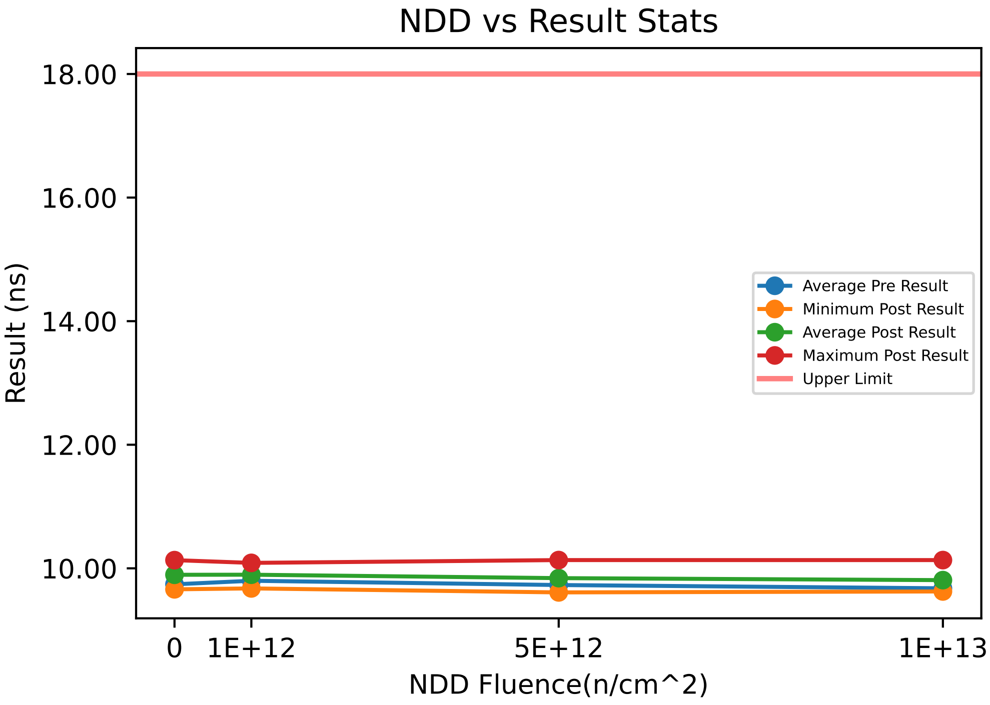
Test Results (Upper Limit = 18.0 (ns))

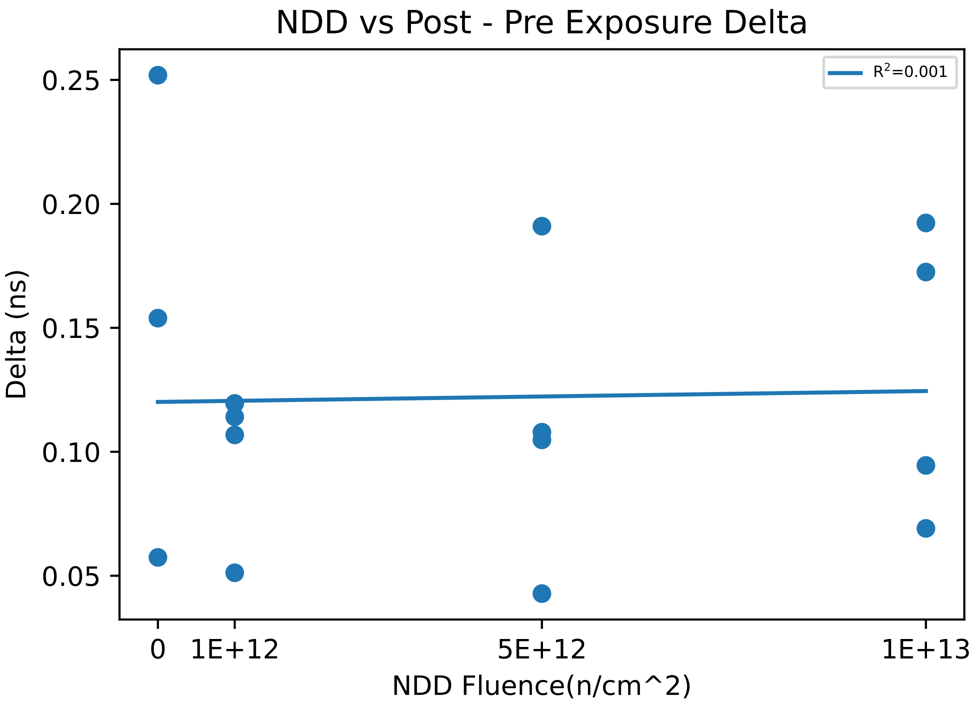
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.766	9.8748	0.1088
2	1e+12	NDD	9.9061	10.086	0.1796
3	1e+12	NDD	9.9403	10.07	0.1293
4	1e+12	NDD	9.7633	10.021	0.2581
5	5e+12	NDD	9.6203	10.077	0.4569
6	5e+12	NDD	9.6528	9.909	0.2562
7	5e+12	NDD	10.04	9.6714	-0.3684
8	5e+12	NDD	9.7511	10.1	0.3484
9	1e+13	NDD	9.3704	9.8767	0.5063
10	1e+13	NDD	9.8757	10.12	0.2446
11	1e+13	NDD	9.8753	10.023	0.1474
12	1e+13	NDD	9.5127	9.9117	0.399
13	0	CORRELATION	9.8808	10.046	0.1647
14	0	CORRELATION	9.7576	10.021	0.2634
15	0	CORRELATION	9.8082	10.088	0.2794

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7576	9.8155	9.8808	0.061927	10.021	10.051	10.088	0.033685	0.1647	0.23583	0.2794	0.062121
1e+12	9.7633	9.8439	9.9403	0.092604	9.8748	10.013	10.086	0.096018	0.1088	0.16895	0.2581	0.066461
5e+12	9.6203	9.766	10.04	0.19082	9.6714	9.9393	10.1	0.1978	-0.3684	0.17328	0.4569	0.37032
1e+13	9.3704	9.6585	9.8757	0.25719	9.8767	9.9828	10.12	0.11077	0.1474	0.32432	0.5063	0.15953

Device Test: 24.14 TIMING|OUT_FALL/OUTH/12/12/0/1000/5/500kHz//@OUT_FALL_12V





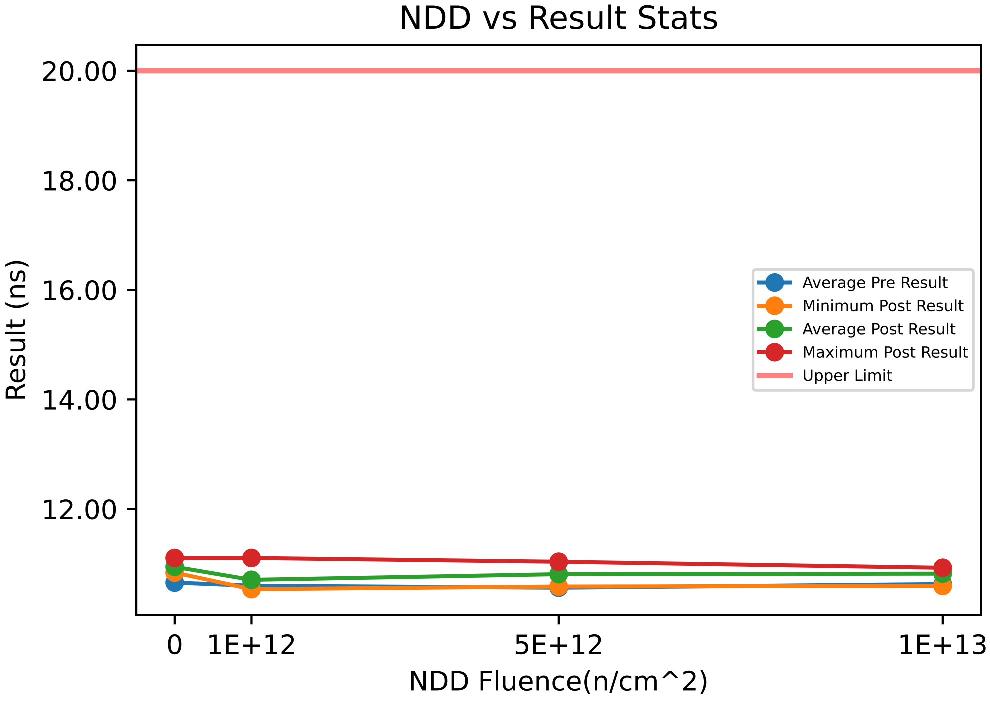
Test Results (Upper Limit = 18.0 (ns))

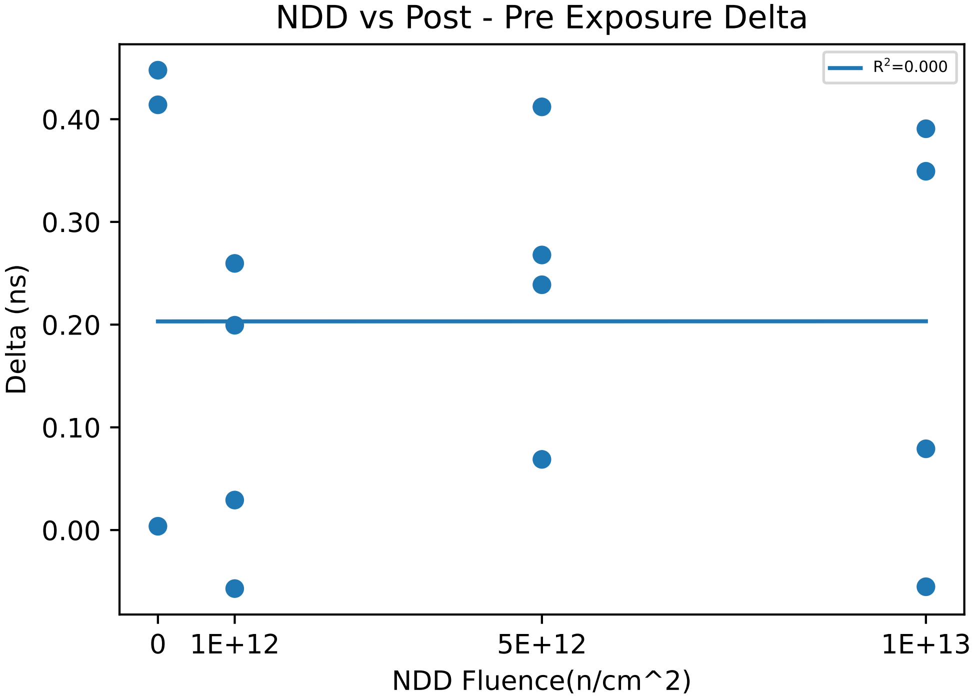
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.8631	9.9772	0.1141
2	1e+12	NDD	9.7949	9.8461	0.0512
3	1e+12	NDD	9.5681	9.6749	0.1068
4	1e+12	NDD	9.9685	10.088	0.1195
5	5e+12	NDD	9.8068	9.8496	0.0428
6	5e+12	NDD	9.4193	9.6103	0.191
7	5e+12	NDD	10.025	10.133	0.1079
8	5e+12	NDD	9.6668	9.7716	0.1048
9	1e+13	NDD	9.4858	9.6583	0.1725
10	1e+13	NDD	10.064	10.133	0.0691
11	1e+13	NDD	9.7236	9.8181	0.0945
12	1e+13	NDD	9.4332	9.6255	0.1923
13	0	CORRELATION	9.8803	10.132	0.2519
14	0	CORRELATION	9.8363	9.8937	0.0574
15	0	CORRELATION	9.5062	9.6601	0.1539

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.5062	9.7409	9.8803	0.20447	9.6601	9.8953	10.132	0.23605	0.0574	0.1544	0.2519	0.097251
1e+12	9.5681	9.7987	9.9685	0.16948	9.6749	9.8965	10.088	0.17779	0.0512	0.0979	0.1195	0.031565
5e+12	9.4193	9.7296	10.025	0.25409	9.6103	9.8412	10.133	0.21875	0.0428	0.11163	0.191	0.060821
1e+13	9.4332	9.6767	10.064	0.28753	9.6255	9.8088	10.133	0.23207	0.0691	0.1321	0.1923	0.059551

Device Test: 24.15 TIMING|OUT_RISE/OUTH/14/14/0/1000/5/500kHz//@OUT_RISE_14V





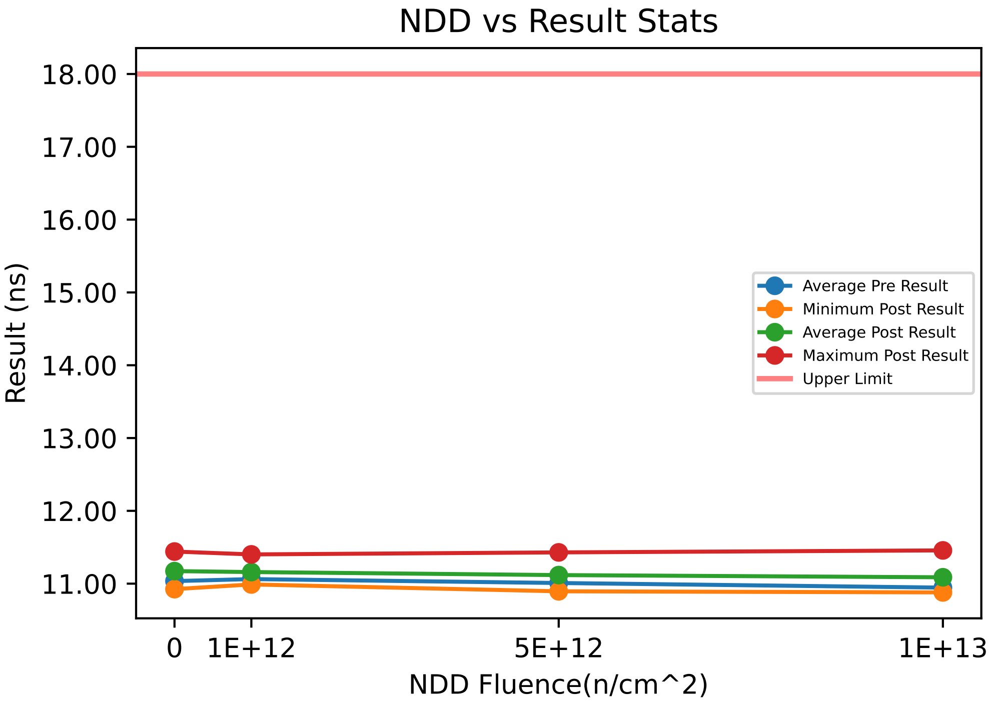
Test Results (Upper Limit = 20.0 (ns))

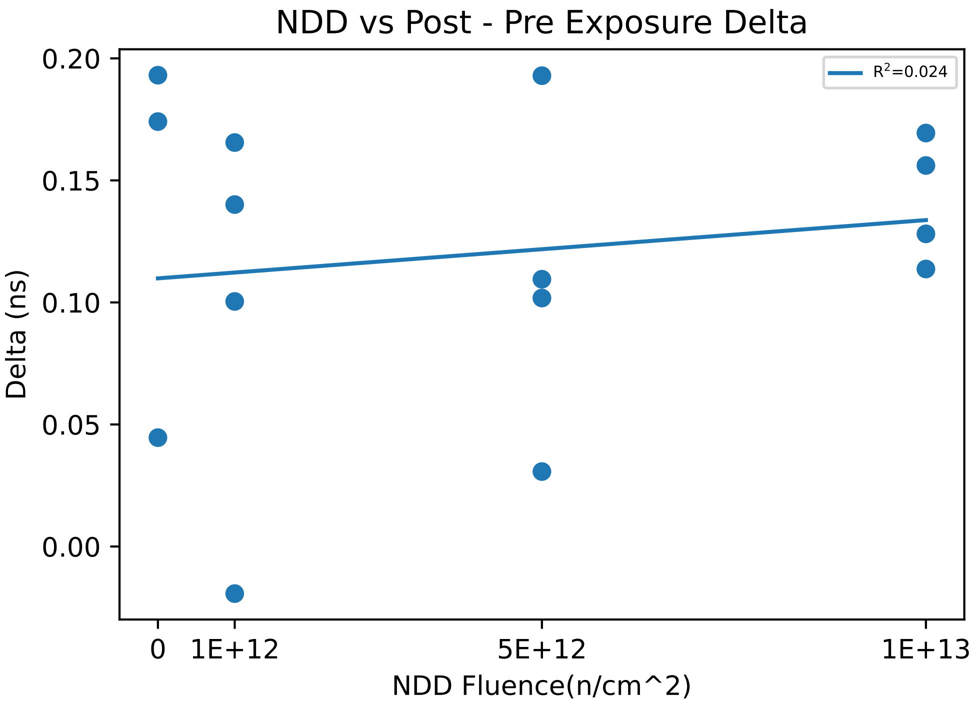
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	10.847	11.106	0.2596
2	1e+12	NDD	10.416	10.615	0.1994
3	1e+12	NDD	10.54	10.569	0.0292
4	1e+12	NDD	10.594	10.537	-0.057
5	5e+12	NDD	10.969	11.037	0.0688
6	5e+12	NDD	10.623	10.891	0.2678
7	5e+12	NDD	10.346	10.585	0.2388
8	5e+12	NDD	10.316	10.728	0.412
9	1e+13	NDD	10.578	10.927	0.3493
10	1e+13	NDD	10.536	10.927	0.3907
11	1e+13	NDD	10.65	10.595	-0.0552
12	1e+13	NDD	10.752	10.831	0.0791
13	0	CORRELATION	10.692	11.106	0.414
14	0	CORRELATION	10.885	10.889	0.0037
15	0	CORRELATION	10.391	10.839	0.4477

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.391	10.656	10.885	0.24898	10.839	10.945	11.106	0.14192	0.0037	0.28847	0.4477	0.24719
1e+12	10.416	10.599	10.847	0.18101	10.537	10.707	11.106	0.26817	-0.057	0.1078	0.2596	0.14694
5e+12	10.316	10.563	10.969	0.3036	10.585	10.81	11.037	0.19656	0.0688	0.24685	0.412	0.14081
1e+13	10.536	10.629	10.752	0.094554	10.595	10.82	10.927	0.15685	-0.0552	0.19097	0.3907	0.21453

Device Test: 24.16 TIMING|OUT_FALL/OUTH/14/14/0/1000/5/500kHz//@OUT_FALL_14V





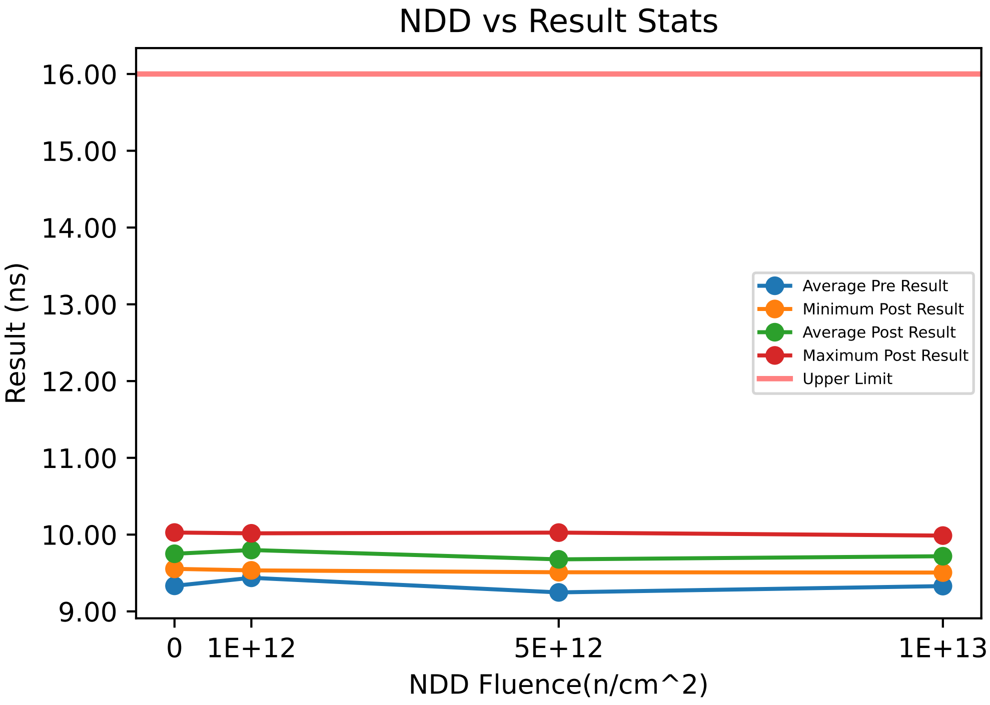
Test Results (Upper Limit = 18.0 (ns))

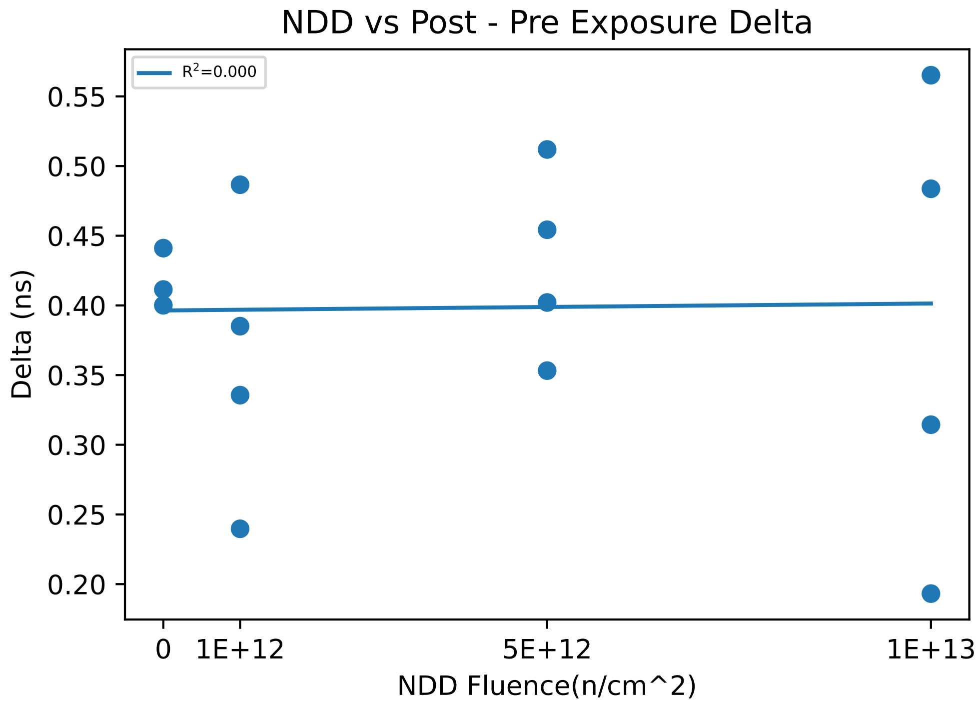
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	11.106	11.207	0.1004
2	1e+12	NDD	11.059	11.04	-0.0193
3	1e+12	NDD	10.824	10.989	0.1655
4	1e+12	NDD	11.262	11.402	0.1401
5	5e+12	NDD	11.036	11.138	0.1018
6	5e+12	NDD	10.785	10.895	0.1095
7	5e+12	NDD	11.236	11.429	0.1929
8	5e+12	NDD	10.978	11.008	0.0307
9	1e+13	NDD	10.772	10.928	0.1561
10	1e+13	NDD	11.287	11.457	0.1694
11	1e+13	NDD	10.972	11.086	0.1137
12	1e+13	NDD	10.752	10.88	0.1281
13	0	CORRELATION	11.248	11.441	0.1931
14	0	CORRELATION	11.107	11.151	0.0446
15	0	CORRELATION	10.751	10.925	0.1741

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.751	11.035	11.248	0.25619	10.925	11.172	11.441	0.25875	0.0446	0.13727	0.1931	0.080812
1e+12	10.824	11.063	11.262	0.18131	10.989	11.159	11.402	0.18639	-0.0193	0.096675	0.1655	0.081826
5e+12	10.785	11.009	11.236	0.18569	10.895	11.118	11.429	0.23031	0.0307	0.10872	0.1929	0.066387
1e+13	10.752	10.946	11.287	0.2485	10.88	11.087	11.457	0.26135	0.1137	0.14182	0.1694	0.025453

Device Test: 24.17 TIMING|OUT_RISE/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_RISE_LDO





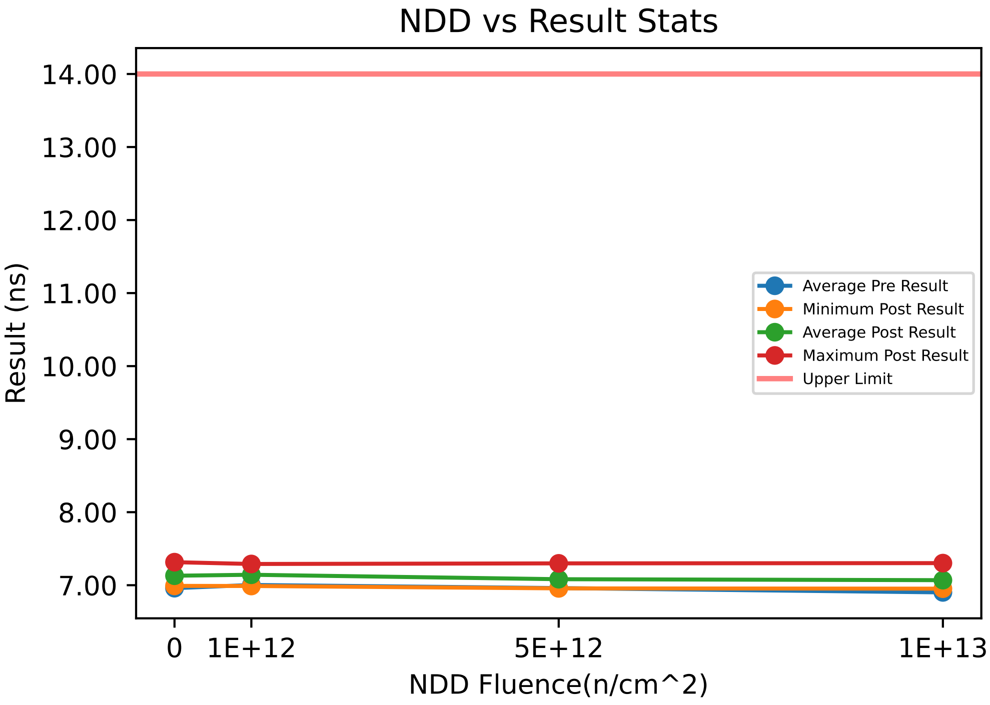
Test Results (Upper Limit = 16.0 (ns))

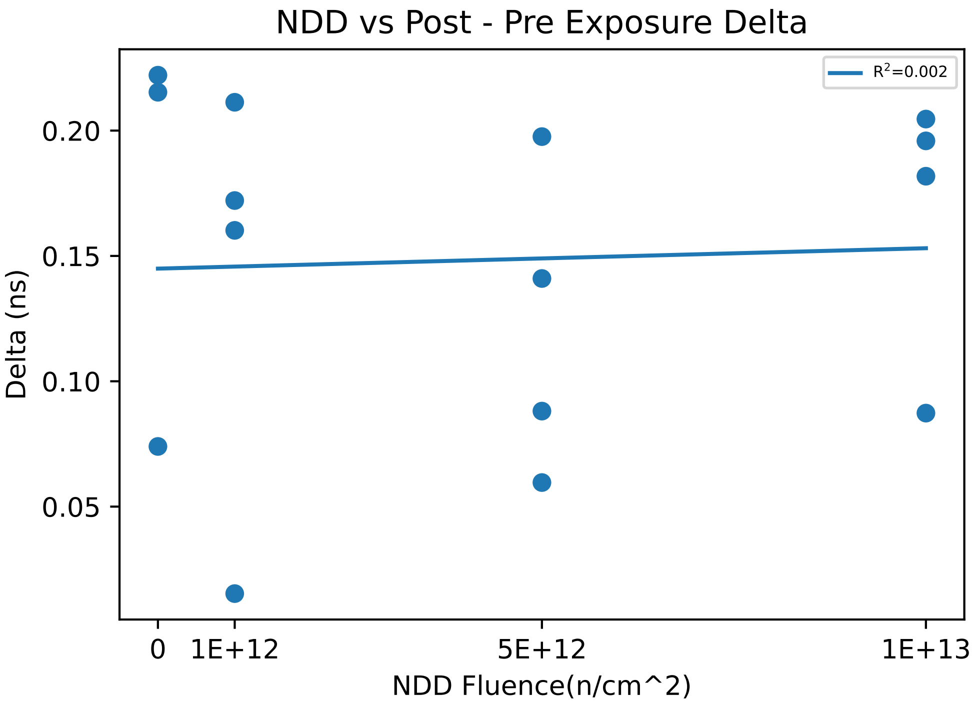
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	9.4697	9.9563	0.4866
2	1e+12	NDD	9.1987	9.5343	0.3356
3	1e+12	NDD	9.4497	9.6894	0.2397
4	1e+12	NDD	9.6318	10.017	0.3851
5	5e+12	NDD	9.0554	9.5097	0.4543
6	5e+12	NDD	9.3114	9.6646	0.3532
7	5e+12	NDD	9.5143	10.026	0.5119
8	5e+12	NDD	9.1082	9.5103	0.4021
9	1e+13	NDD	9.1348	9.7	0.5652
10	1e+13	NDD	9.5037	9.9874	0.4837
11	1e+13	NDD	9.3126	9.5058	0.1932
12	1e+13	NDD	9.3668	9.6812	0.3144
13	0	CORRELATION	9.586	10.027	0.4411
14	0	CORRELATION	9.1426	9.554	0.4114
15	0	CORRELATION	9.2703	9.6704	0.4001

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.1426	9.333	9.586	0.22825	9.554	9.7505	10.027	0.24651	0.4001	0.41753	0.4411	0.021177
1e+12	9.1987	9.4375	9.6318	0.17885	9.5343	9.7992	10.017	0.22679	0.2397	0.36175	0.4866	0.10281
5e+12	9.0554	9.2473	9.5143	0.20942	9.5097	9.6777	10.026	0.2435	0.3532	0.43037	0.5119	0.06825
1e+13	9.1348	9.3295	9.5037	0.15268	9.5058	9.7186	9.9874	0.1994	0.1932	0.38912	0.5652	0.16725

Device Test: 24.18 TIMING|OUT_FALL/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_FALL_LDO





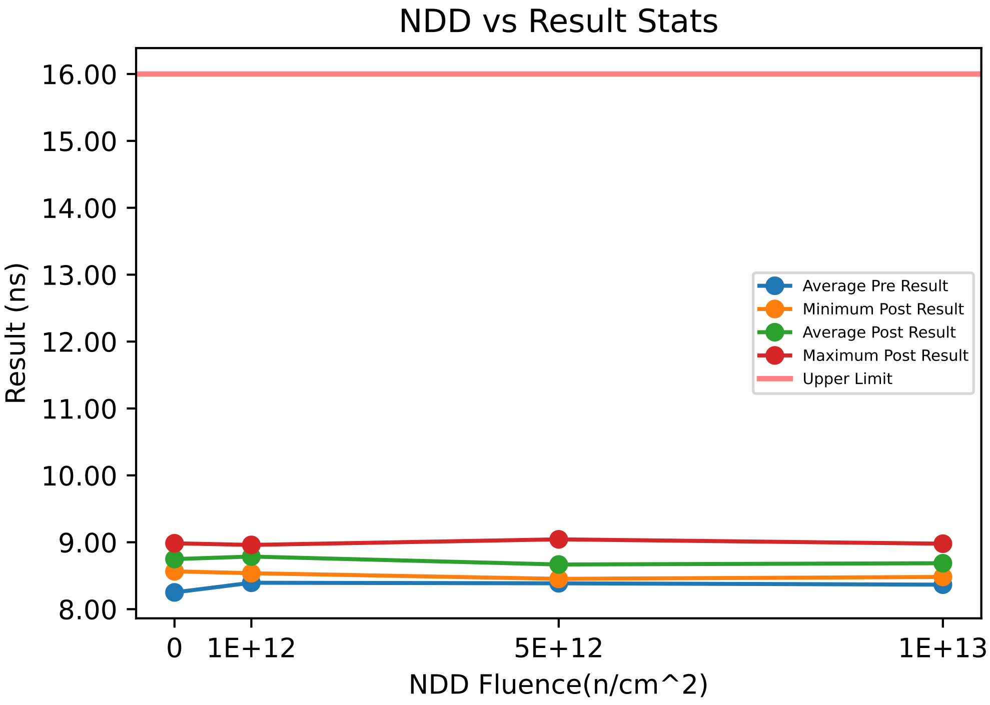
Test Results (Upper Limit = 14.0 (ns))

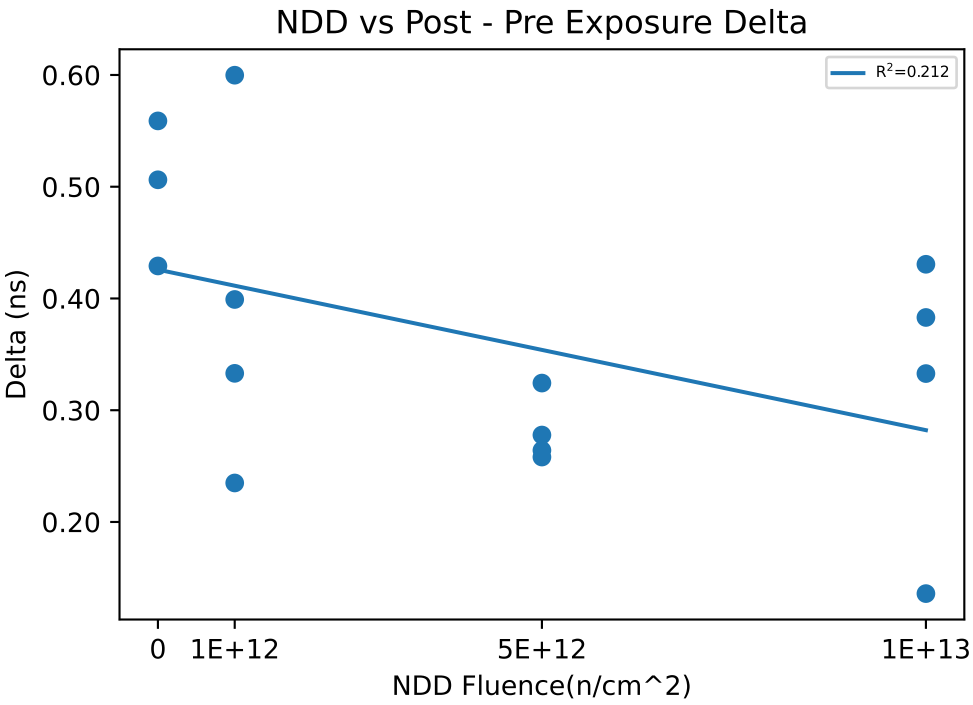
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.0799	7.252	0.1721
2	1e+12	NDD	7.025	7.0403	0.0153
3	1e+12	NDD	6.7777	6.989	0.2113
4	1e+12	NDD	7.1304	7.2906	0.1602
5	5e+12	NDD	6.9699	7.058	0.0881
6	5e+12	NDD	6.7589	6.9565	0.1976
7	5e+12	NDD	7.1579	7.2989	0.141
8	5e+12	NDD	6.9554	7.015	0.0596
9	1e+13	NDD	6.7642	6.9688	0.2046
10	1e+13	NDD	7.1206	7.3024	0.1818
11	1e+13	NDD	6.9641	7.0514	0.0873
12	1e+13	NDD	6.7567	6.9526	0.1959
13	0	CORRELATION	7.0932	7.3153	0.2221
14	0	CORRELATION	7.0091	7.0831	0.074
15	0	CORRELATION	6.7754	6.9907	0.2153

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7754	6.9592	7.0932	0.16466	6.9907	7.1297	7.3153	0.16724	0.074	0.17047	0.2221	0.083612
1e+12	6.7777	7.0033	7.1304	0.15641	6.989	7.143	7.2906	0.15048	0.0153	0.13972	0.2113	0.085775
5e+12	6.7589	6.9605	7.1579	0.16302	6.9565	7.0821	7.2989	0.1504	0.0596	0.12157	0.1976	0.060879
1e+13	6.7567	6.9014	7.1206	0.17487	6.9526	7.0688	7.3024	0.16163	0.0873	0.1674	0.2046	0.05422

Device Test: 24.19 TIMING|OUT_RISE/OUTH/5/12/0/1000/5/500kHz//@OUT_RISE_LDO





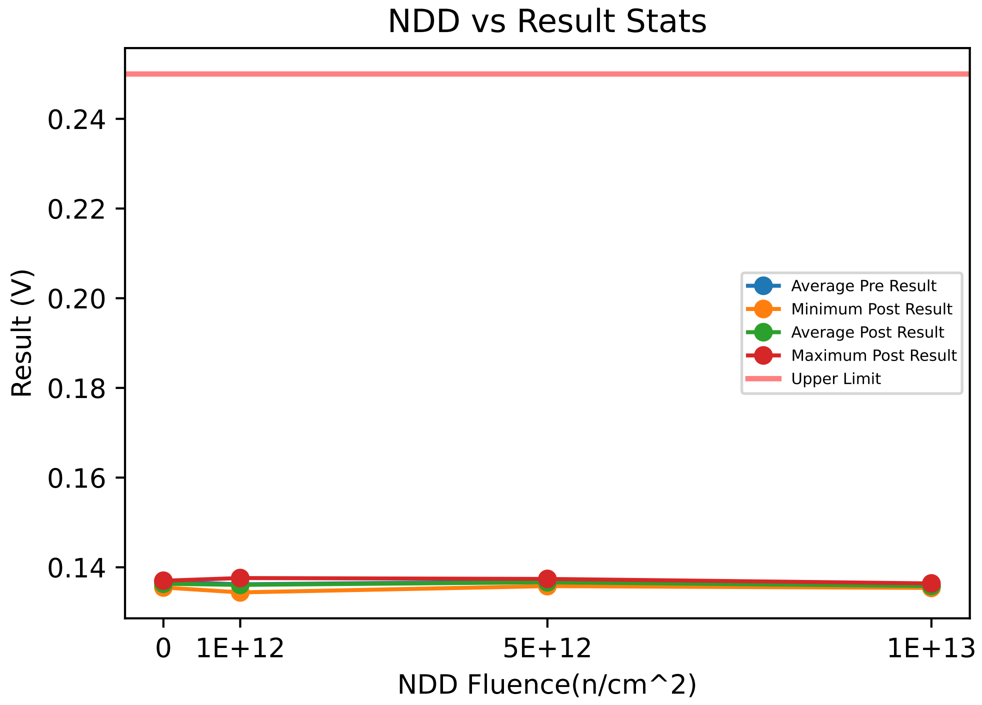
Test Results (Upper Limit = 16.0 (ns))

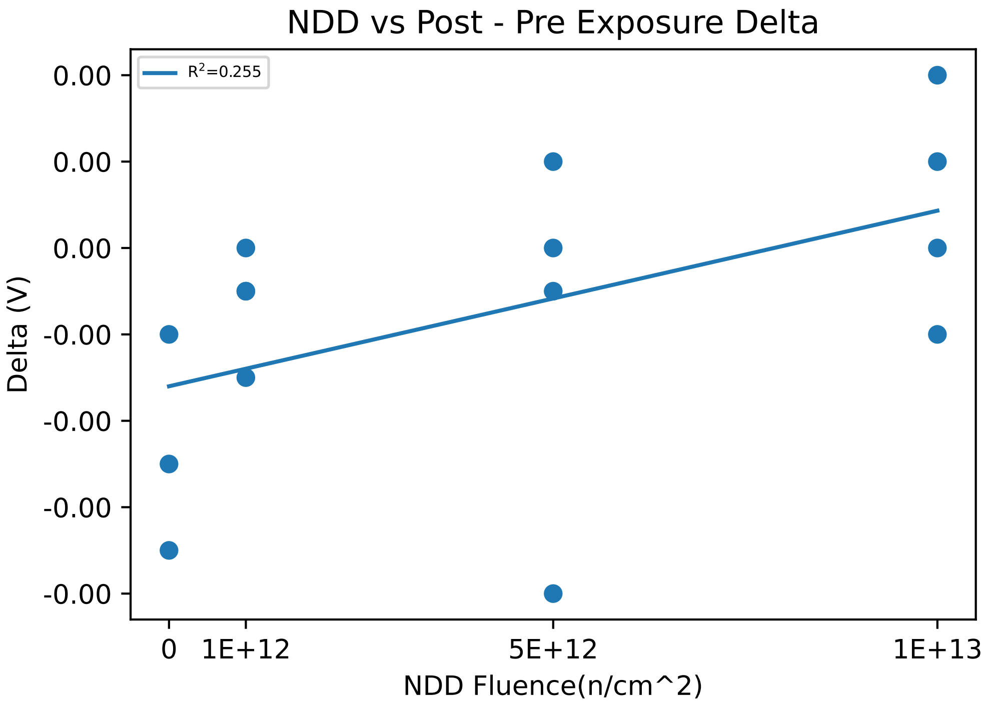
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.3605	8.9603	0.5998
2	1e+12	NDD	8.2043	8.5373	0.333
3	1e+12	NDD	8.2953	8.6944	0.3991
4	1e+12	NDD	8.7186	8.9535	0.2349
5	5e+12	NDD	8.2826	8.5467	0.2641
6	5e+12	NDD	8.3688	8.6269	0.2581
7	5e+12	NDD	8.7659	9.0437	0.2778
8	5e+12	NDD	8.1288	8.4531	0.3243
9	1e+13	NDD	8.317	8.6498	0.3328
10	1e+13	NDD	8.5481	8.9787	0.4306
11	1e+13	NDD	8.3455	8.4814	0.1359
12	1e+13	NDD	8.2536	8.6366	0.383
13	0	CORRELATION	8.4786	8.9848	0.5062
14	0	CORRELATION	8.1363	8.5654	0.4291
15	0	CORRELATION	8.1367	8.6956	0.5589

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1363	8.2505	8.4786	0.19751	8.5654	8.7486	8.9848	0.21466	0.4291	0.49807	0.5589	0.065281
1e+12	8.2043	8.3947	8.7186	0.22525	8.5373	8.7864	8.9603	0.20711	0.2349	0.3917	0.5998	0.15426
5e+12	8.1288	8.3865	8.7659	0.2717	8.4531	8.6676	9.0437	0.2606	0.2581	0.28107	0.3243	0.029973
1e+13	8.2536	8.366	8.5481	0.1273	8.4814	8.6866	8.9787	0.20919	0.1359	0.32058	0.4306	0.12943

Device Test: 24.2 LEVEL|HIGH_LEVEL/OUTH/4.5/4.5/0/0/4.5/500kHz//@OUT_VOH


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

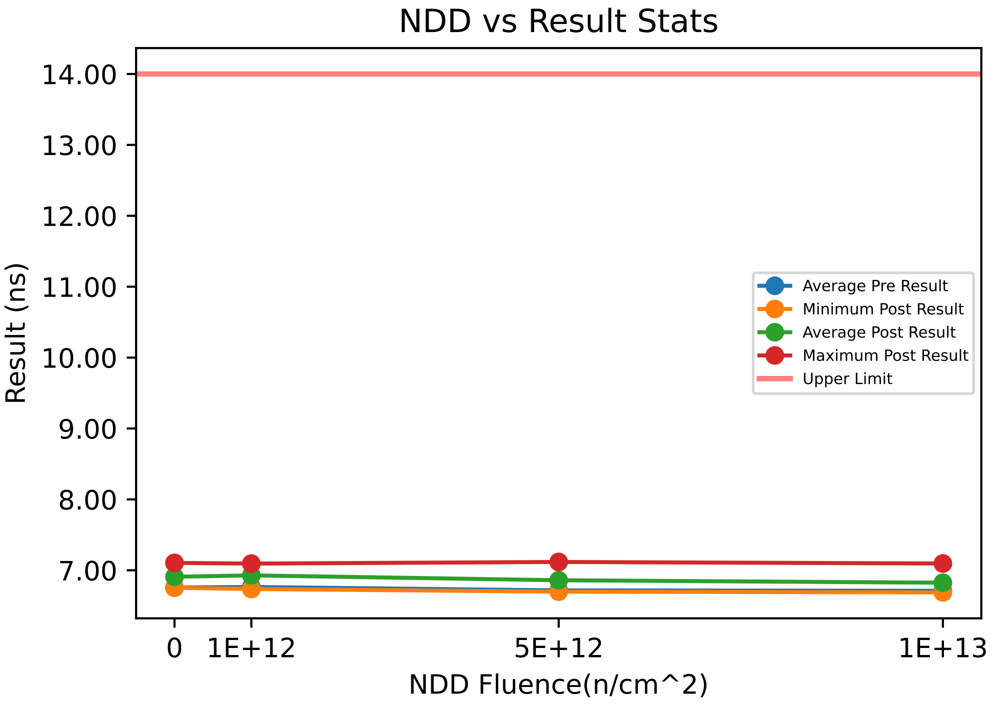
Test Results (Upper Limit = 0.25 (V))

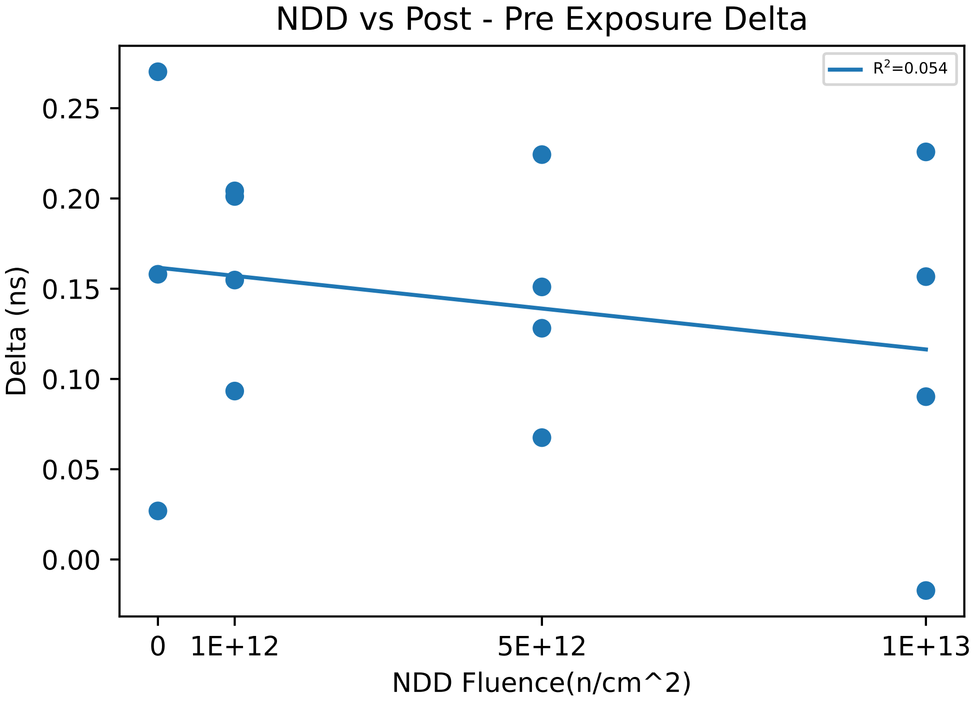
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1345	0.1344	-0.0001
2	1e+12	NDD	0.1372	0.1371	-0.0001
3	1e+12	NDD	0.1376	0.1376	0
4	1e+12	NDD	0.1355	0.1352	-0.0003
5	5e+12	NDD	0.1374	0.1366	-0.0008
6	5e+12	NDD	0.1356	0.1358	0.0002
7	5e+12	NDD	0.1375	0.1374	-0.0001
8	5e+12	NDD	0.1368	0.1368	0
9	1e+13	NDD	0.1355	0.1359	0.0004
10	1e+13	NDD	0.1358	0.1356	-0.0002
11	1e+13	NDD	0.1364	0.1364	0
12	1e+13	NDD	0.1352	0.1354	0.0002
13	0	CORRELATION	0.1362	0.1355	-0.0007
14	0	CORRELATION	0.137	0.1365	-0.0005
15	0	CORRELATION	0.1372	0.137	-0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1362	0.1368	0.1372	0.00052915	0.1355	0.13633	0.137	0.00076376	-0.0007	-0.00046667	-0.0002	0.00025166
1e+12	0.1345	0.1362	0.1376	0.0014537	0.1344	0.13608	0.1376	0.0015218	-0.0003	-0.000125	0	0.00012583
5e+12	0.1356	0.13683	0.1375	0.00087321	0.1358	0.13665	0.1374	0.00066081	-0.0008	-0.000175	0.0002	0.00043493
1e+13	0.1352	0.13572	0.1364	0.00051235	0.1354	0.13583	0.1364	0.00043493	-0.0002	0.0001	0.0004	0.0002582

Device Test: 24.20 TIMING|OUT_FALL/OUTH/5/12/0/1000/5/500kHz//@OUT_FALL_LDO





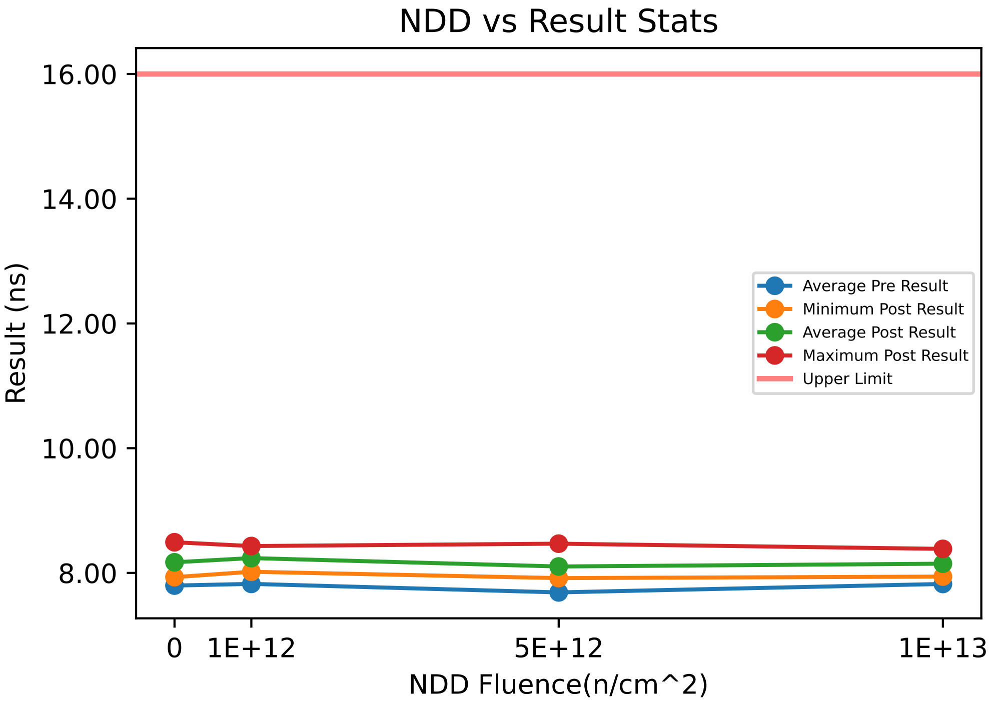
Test Results (Upper Limit = 14.0 (ns))

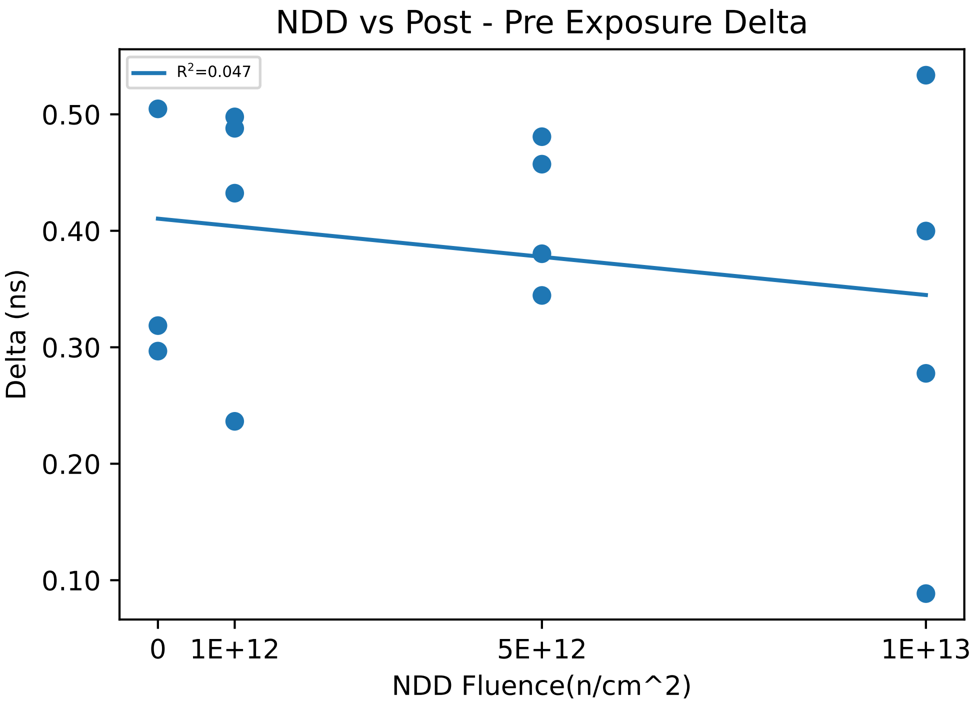
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.8422	7.0433	0.2011
2	1e+12	NDD	6.7461	6.8394	0.0933
3	1e+12	NDD	6.5316	6.7358	0.2042
4	1e+12	NDD	6.94	7.0948	0.1548
5	5e+12	NDD	6.6994	6.8275	0.1281
6	5e+12	NDD	6.4745	6.6988	0.2243
7	5e+12	NDD	6.9664	7.1174	0.151
8	5e+12	NDD	6.7272	6.7947	0.0675
9	1e+13	NDD	6.4845	6.7103	0.2258
10	1e+13	NDD	6.9393	7.096	0.1567
11	1e+13	NDD	6.8219	6.8047	-0.0172
12	1e+13	NDD	6.598	6.6882	0.0902
13	0	CORRELATION	6.9465	7.1045	0.158
14	0	CORRELATION	6.8403	6.8672	0.0269
15	0	CORRELATION	6.4836	6.7538	0.2702

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4836	6.7568	6.9465	0.24248	6.7538	6.9085	7.1045	0.17896	0.0269	0.1517	0.2702	0.12177
1e+12	6.5316	6.765	6.94	0.17456	6.7358	6.9283	7.0948	0.16922	0.0933	0.16335	0.2042	0.051878
5e+12	6.4745	6.7169	6.9664	0.20118	6.6988	6.8596	7.1174	0.18033	0.0675	0.14272	0.2243	0.064796
1e+13	6.4845	6.7109	6.9393	0.20695	6.6882	6.8248	7.096	0.18773	-0.0172	0.11388	0.2258	0.10344

Device Test: 24.21 TIMING|OUT_RISE/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_RISE_LDO


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

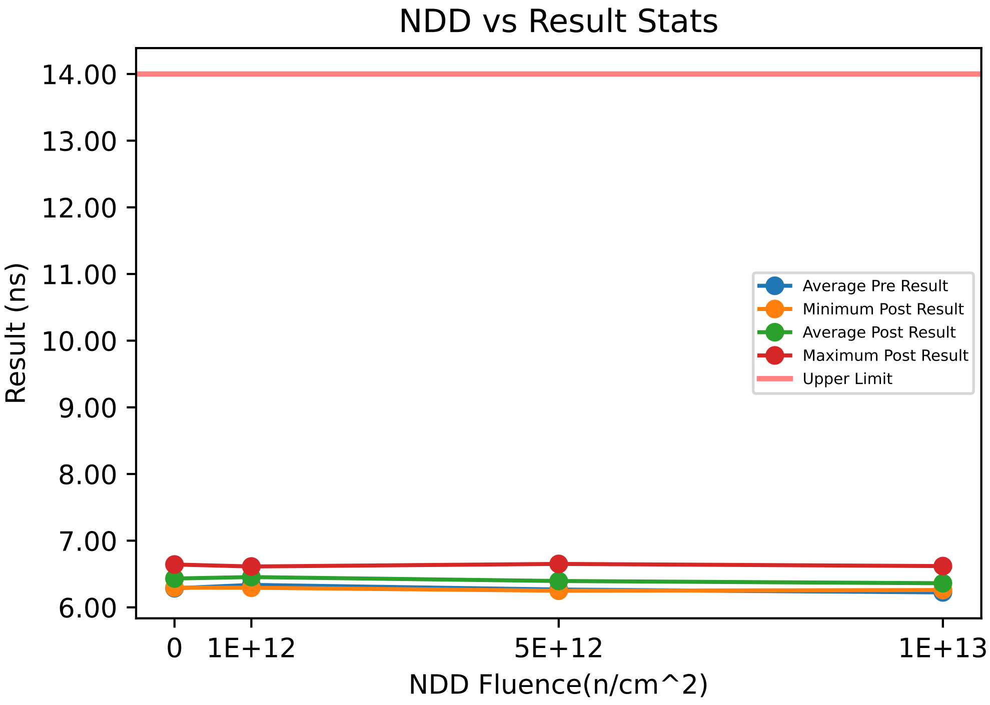
Test Results (Upper Limit = 16.0 (ns))

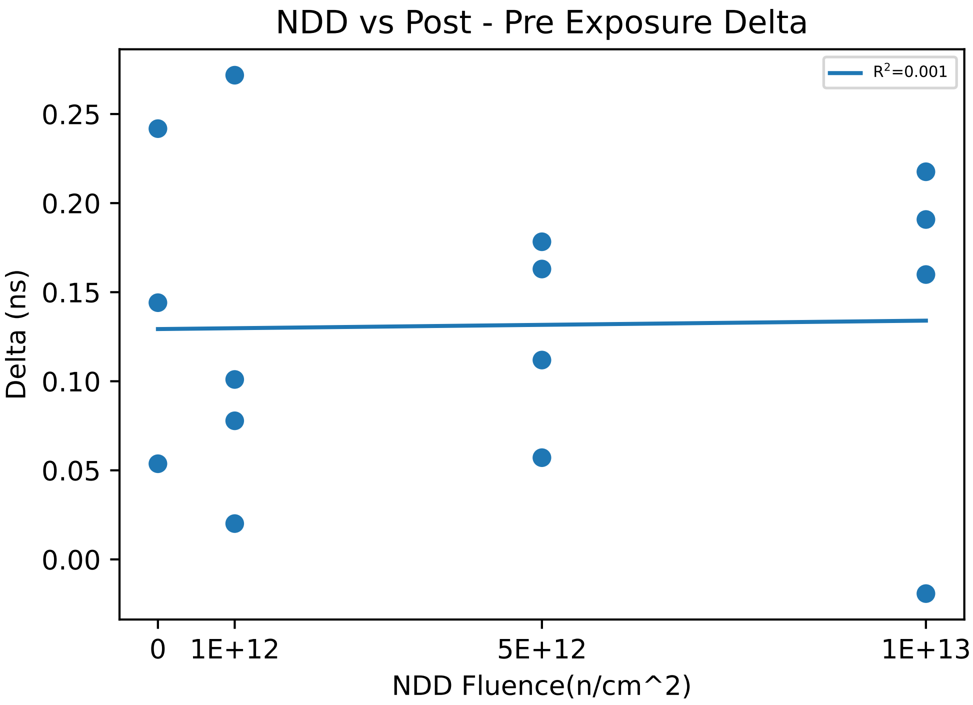
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	7.9986	8.4309	0.4323
2	1e+12	NDD	7.5209	8.0187	0.4978
3	1e+12	NDD	7.858	8.0944	0.2364
4	1e+12	NDD	7.92	8.408	0.488
5	5e+12	NDD	7.5749	7.9552	0.3803
6	5e+12	NDD	7.5916	8.0724	0.4808
7	5e+12	NDD	8.1244	8.4689	0.3445
8	5e+12	NDD	7.4598	7.917	0.4572
9	1e+13	NDD	8.0279	8.1164	0.0885
10	1e+13	NDD	7.9856	8.3854	0.3998
11	1e+13	NDD	7.6637	7.9413	0.2776
12	1e+13	NDD	7.6154	8.149	0.5336
13	0	CORRELATION	7.9871	8.4918	0.5047
14	0	CORRELATION	7.6136	7.9322	0.3186
15	0	CORRELATION	7.7907	8.0874	0.2967

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6136	7.7971	7.9871	0.18683	7.9322	8.1705	8.4918	0.2889	0.2967	0.37333	0.5047	0.11429
1e+12	7.5209	7.8244	7.9986	0.21034	8.0187	8.238	8.4309	0.21199	0.2364	0.41363	0.4978	0.12162
5e+12	7.4598	7.6877	8.1244	0.29699	7.917	8.1034	8.4689	0.25249	0.3445	0.4157	0.4808	0.063987
1e+13	7.6154	7.8232	8.0279	0.21362	7.9413	8.148	8.3854	0.18265	0.0885	0.32487	0.5336	0.18911

Device Test: 24.22 TIMING|OUT_FALL/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_FALL_LDO


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

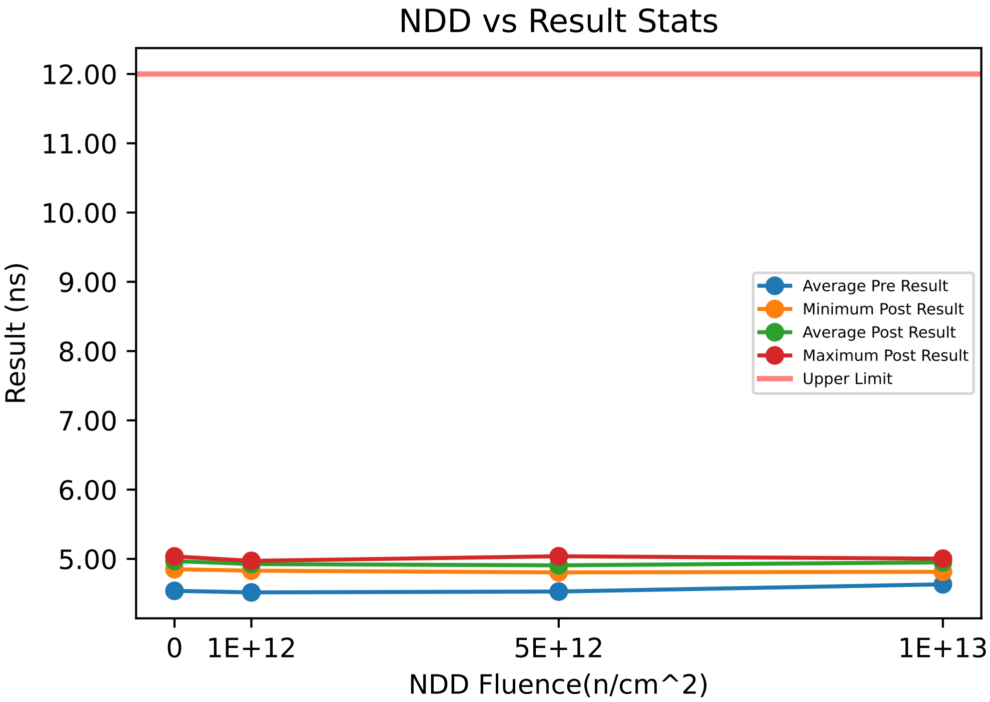
Test Results (Upper Limit = 14.0 (ns))

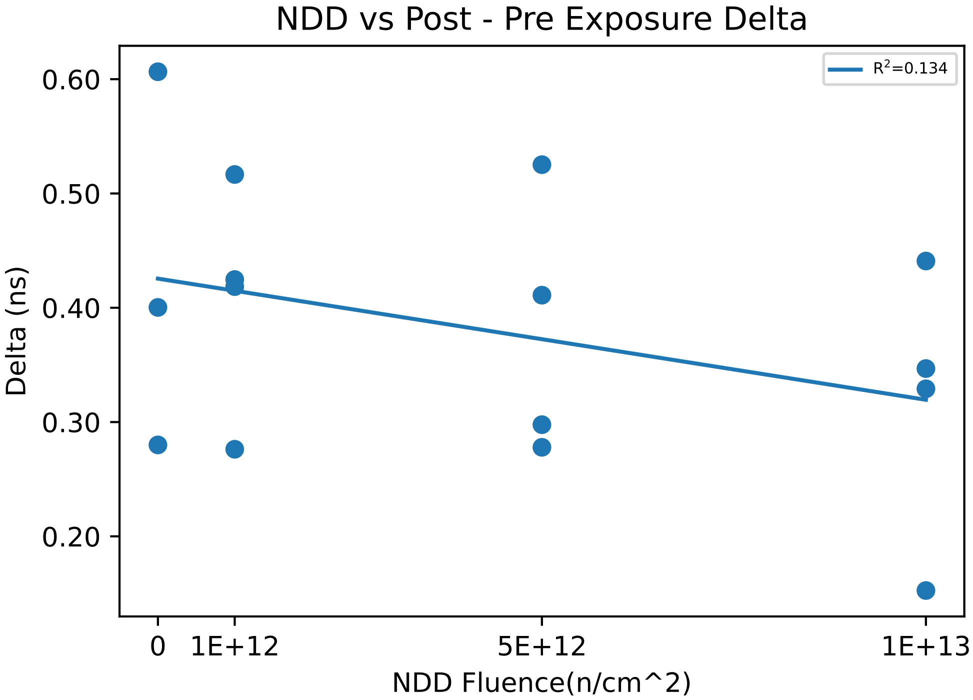
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	6.4671	6.5681	0.101
2	1e+12	NDD	6.3216	6.3417	0.0201
3	1e+12	NDD	6.022	6.2938	0.2718
4	1e+12	NDD	6.5351	6.6129	0.0778
5	5e+12	NDD	6.3037	6.3608	0.0571
6	5e+12	NDD	6.0862	6.2492	0.163
7	5e+12	NDD	6.4729	6.6512	0.1783
8	5e+12	NDD	6.2065	6.3184	0.1119
9	1e+13	NDD	6.1072	6.2671	0.1599
10	1e+13	NDD	6.4279	6.6187	0.1908
11	1e+13	NDD	6.3193	6.3001	-0.0192
12	1e+13	NDD	6.0422	6.2598	0.2176
13	0	CORRELATION	6.4984	6.6425	0.1441
14	0	CORRELATION	6.3056	6.3593	0.0537
15	0	CORRELATION	6.0534	6.2952	0.2418

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0534	6.2858	6.4984	0.22316	6.2952	6.4323	6.6425	0.18481	0.0537	0.14653	0.2418	0.094074
1e+12	6.022	6.3365	6.5351	0.22776	6.2938	6.4541	6.6129	0.15973	0.0201	0.11767	0.2718	0.10823
5e+12	6.0862	6.2673	6.4729	0.16339	6.2492	6.3949	6.6512	0.17695	0.0571	0.12757	0.1783	0.054895
1e+13	6.0422	6.2241	6.4279	0.18014	6.2598	6.3614	6.6187	0.17241	-0.0192	0.13727	0.2176	0.10695

Device Test: 24.23 TIMING|OUT_RISE/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_RISE_220PF





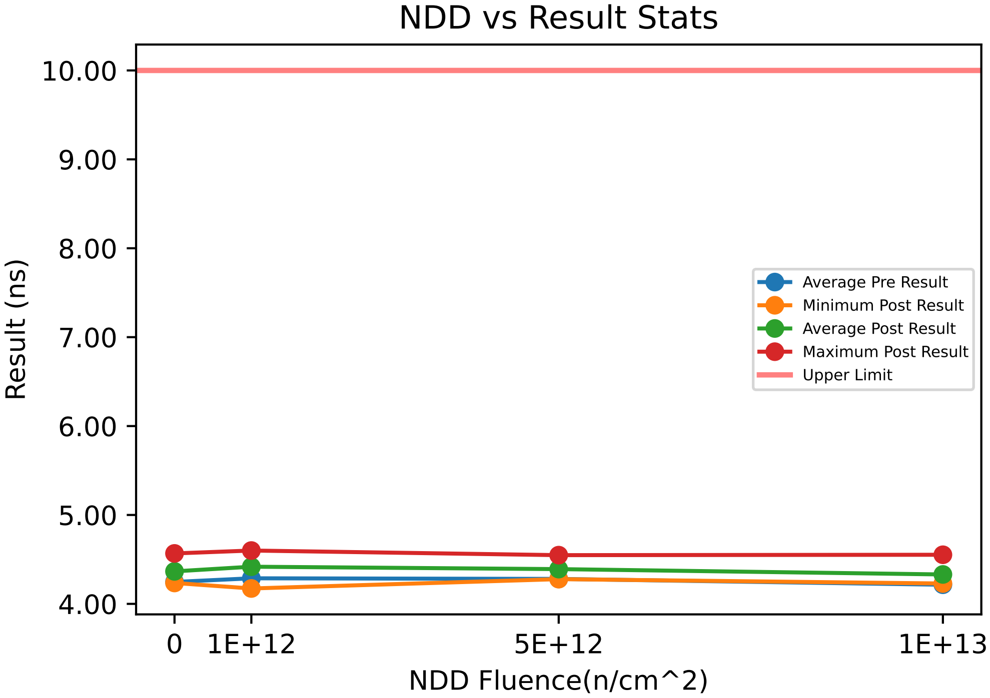
Test Results (Upper Limit = 12.0 (ns))

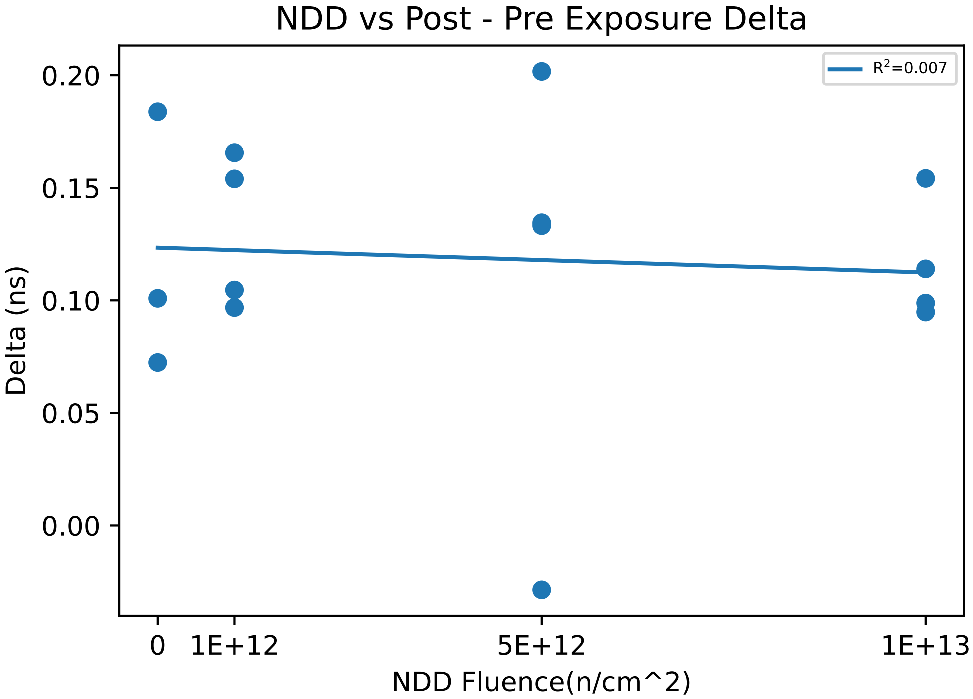
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.428	4.9446	0.5166
2	1e+12	NDD	4.4117	4.8302	0.4185
3	1e+12	NDD	4.679	4.9552	0.2762
4	1e+12	NDD	4.5471	4.9718	0.4247
5	5e+12	NDD	4.5276	4.8055	0.2779
6	5e+12	NDD	4.5491	4.9601	0.411
7	5e+12	NDD	4.513	5.0382	0.5252
8	5e+12	NDD	4.5258	4.8235	0.2977
9	1e+13	NDD	4.5626	5.0035	0.4409
10	1e+13	NDD	4.6593	4.9884	0.3291
11	1e+13	NDD	4.4671	4.8139	0.3468
12	1e+13	NDD	4.8426	4.9952	0.1526
13	0	CORRELATION	4.6353	5.0356	0.4003
14	0	CORRELATION	4.5709	4.8509	0.28
15	0	CORRELATION	4.4106	5.0171	0.6065

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4106	4.5389	4.6353	0.11571	4.8509	4.9679	5.0356	0.10172	0.28	0.42893	0.6065	0.16512
1e+12	4.4117	4.5164	4.679	0.12404	4.8302	4.9254	4.9718	0.064479	0.2762	0.409	0.5166	0.099248
5e+12	4.513	4.5289	4.5491	0.014968	4.8055	4.9068	5.0382	0.11152	0.2779	0.37795	0.5252	0.11435
1e+13	4.4671	4.6329	4.8426	0.16032	4.8139	4.9503	5.0035	0.091109	0.1526	0.31735	0.4409	0.12029

Device Test: 24.24 TIMING|OUT_FALL/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_FALL_220PF





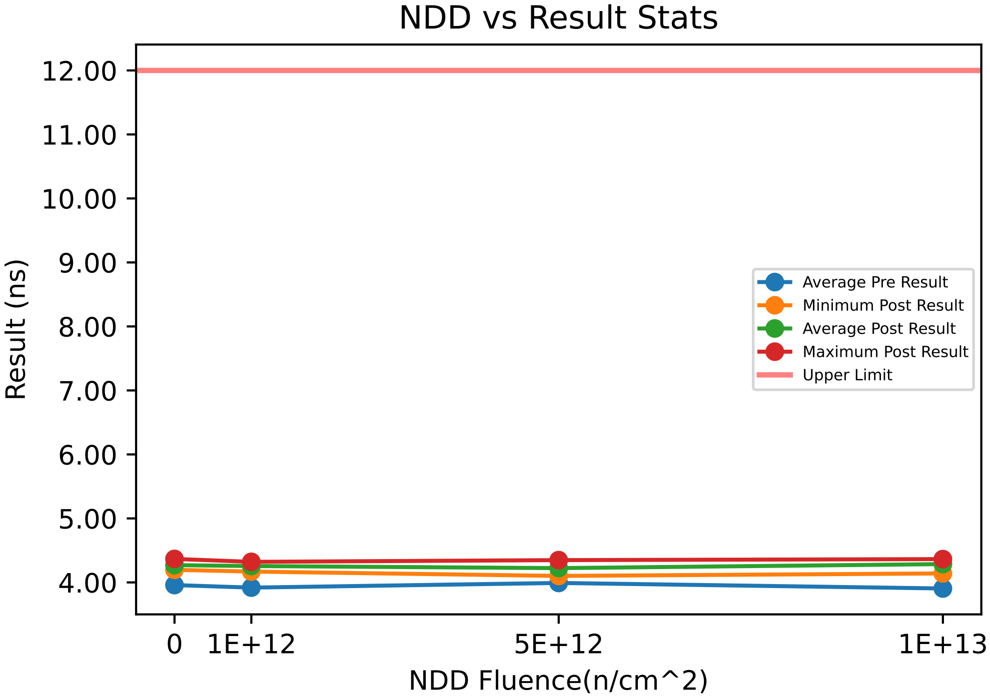
Test Results (Upper Limit = 10.0 (ns))

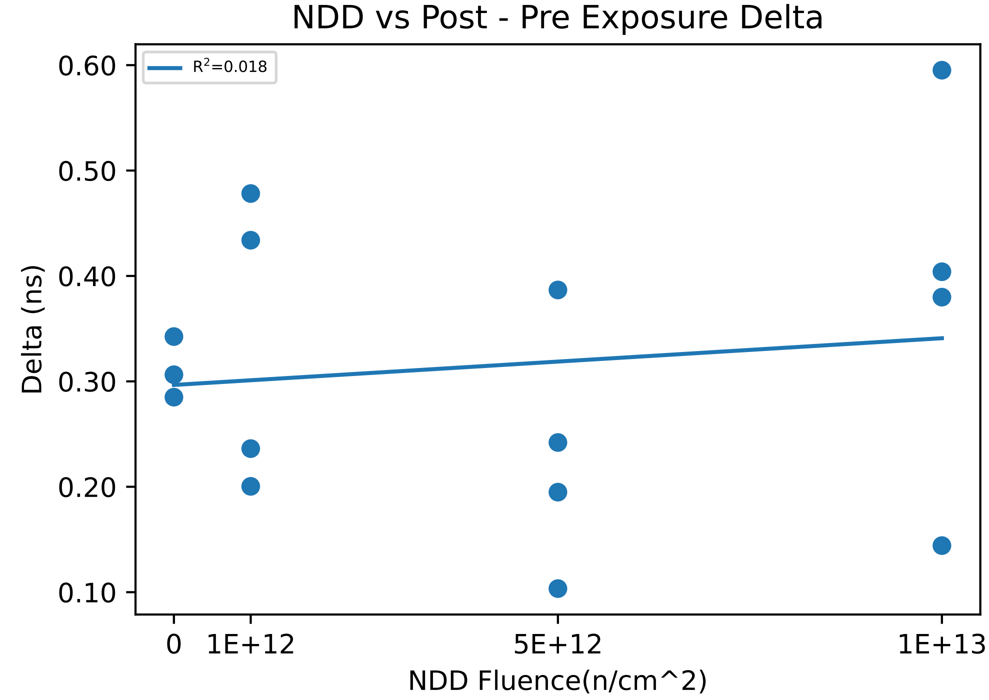
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.4383	4.5429	0.1046
2	1e+12	NDD	4.2017	4.3557	0.154
3	1e+12	NDD	4.0075	4.1731	0.1656
4	1e+12	NDD	4.503	4.5998	0.0968
5	5e+12	NDD	4.1844	4.3189	0.1345
6	5e+12	NDD	4.0763	4.278	0.2017
7	5e+12	NDD	4.4147	4.5479	0.1332
8	5e+12	NDD	4.4473	4.4187	-0.0286
9	1e+13	NDD	4.1229	4.2369	0.114
10	1e+13	NDD	4.4575	4.5523	0.0948
11	1e+13	NDD	4.2062	4.305	0.0988
12	1e+13	NDD	4.0749	4.2291	0.1542
13	0	CORRELATION	4.4665	4.5674	0.1009
14	0	CORRELATION	4.2217	4.2941	0.0724
15	0	CORRELATION	4.0513	4.2351	0.1838

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0513	4.2465	4.4665	0.20871	4.2351	4.3655	4.5674	0.17729	0.0724	0.11903	0.1838	0.057871
1e+12	4.0075	4.2876	4.503	0.22726	4.1731	4.4179	4.5998	0.19366	0.0968	0.13025	0.1656	0.034595
5e+12	4.0763	4.2807	4.4473	0.1796	4.278	4.3909	4.5479	0.12021	-0.0286	0.1102	0.2017	0.097907
1e+13	4.0749	4.2154	4.4575	0.17029	4.2291	4.3308	4.5523	0.15153	0.0948	0.11545	0.1542	0.027125

Device Test: 24.25 TIMING|OUT_RISE/OUTH/5/12/0/220/5/500kHz//@OUT_RISE_220PF





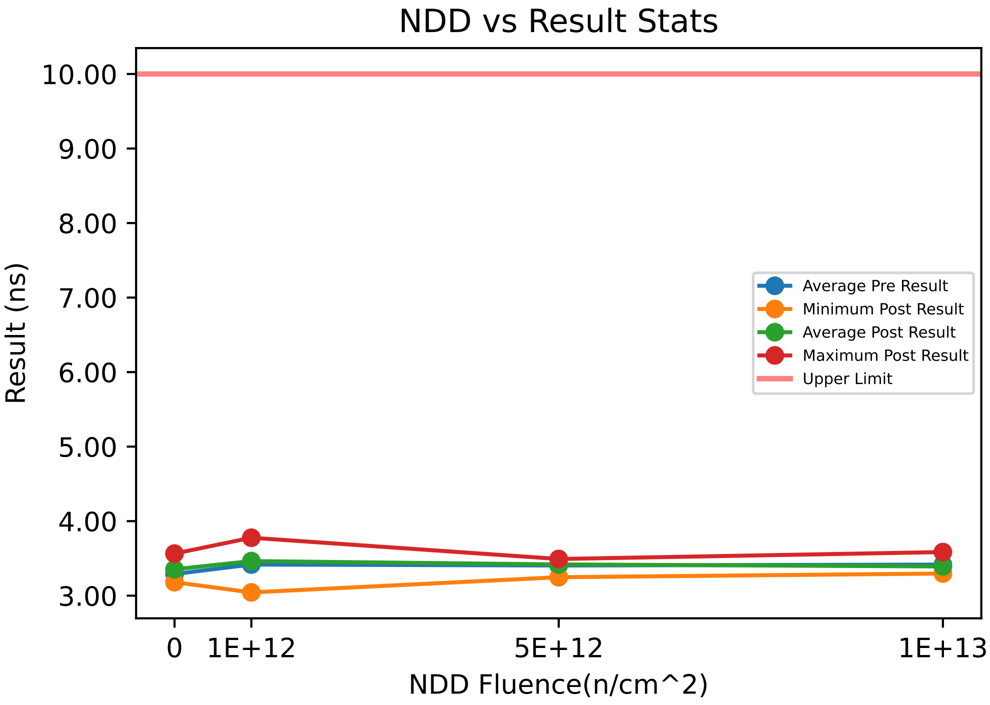
Test Results (Upper Limit = 12.0 (ns))

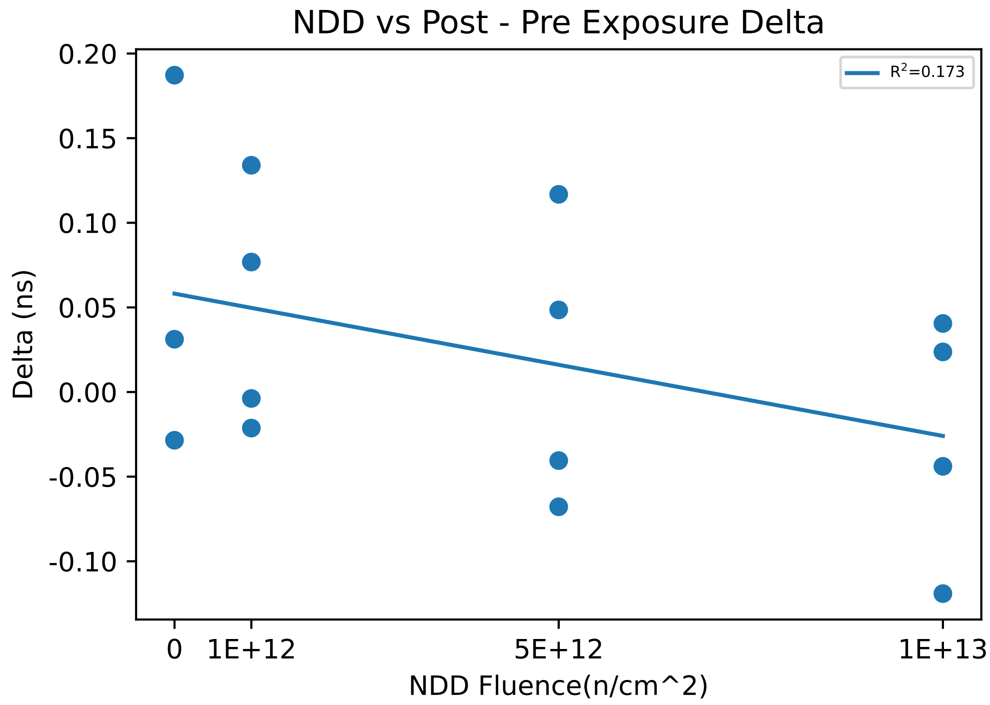
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.0624	4.2628	0.2004
2	1e+12	NDD	3.9335	4.1697	0.2362
3	1e+12	NDD	3.8875	4.3214	0.4339
4	1e+12	NDD	3.7917	4.2699	0.4782
5	5e+12	NDD	3.968	4.1629	0.1949
6	5e+12	NDD	4.0388	4.2808	0.242
7	5e+12	NDD	3.9617	4.3484	0.3867
8	5e+12	NDD	3.9982	4.1016	0.1034
9	1e+13	NDD	3.9199	4.3239	0.404
10	1e+13	NDD	3.9363	4.3162	0.3799
11	1e+13	NDD	3.9962	4.1404	0.1442
12	1e+13	NDD	3.769	4.3642	0.5952
13	0	CORRELATION	4.0607	4.367	0.3063
14	0	CORRELATION	3.9117	4.1967	0.285
15	0	CORRELATION	3.9036	4.2461	0.3425

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9036	3.9587	4.0607	0.088456	4.1967	4.2699	4.367	0.087616	0.285	0.31127	0.3425	0.02907
1e+12	3.7917	3.9188	4.0624	0.1125	4.1697	4.256	4.3214	0.063151	0.2004	0.33717	0.4782	0.13922
5e+12	3.9617	3.9917	4.0388	0.035225	4.1016	4.2234	4.3484	0.11168	0.1034	0.23175	0.3867	0.11825
1e+13	3.769	3.9054	3.9962	0.096634	4.1404	4.2862	4.3642	0.099437	0.1442	0.38082	0.5952	0.18483

Device Test: 24.26 TIMING|OUT_FALL/OUTH/5/12/0/220/5/500kHz//@OUT_FALL_220PF


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

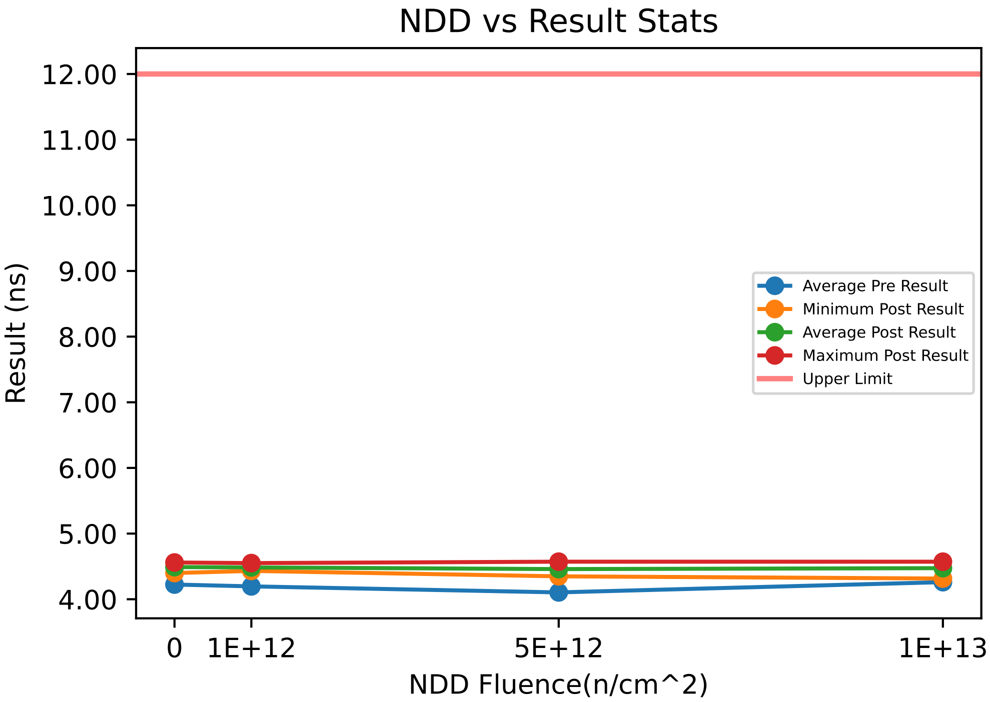
Test Results (Upper Limit = 10.0 (ns))

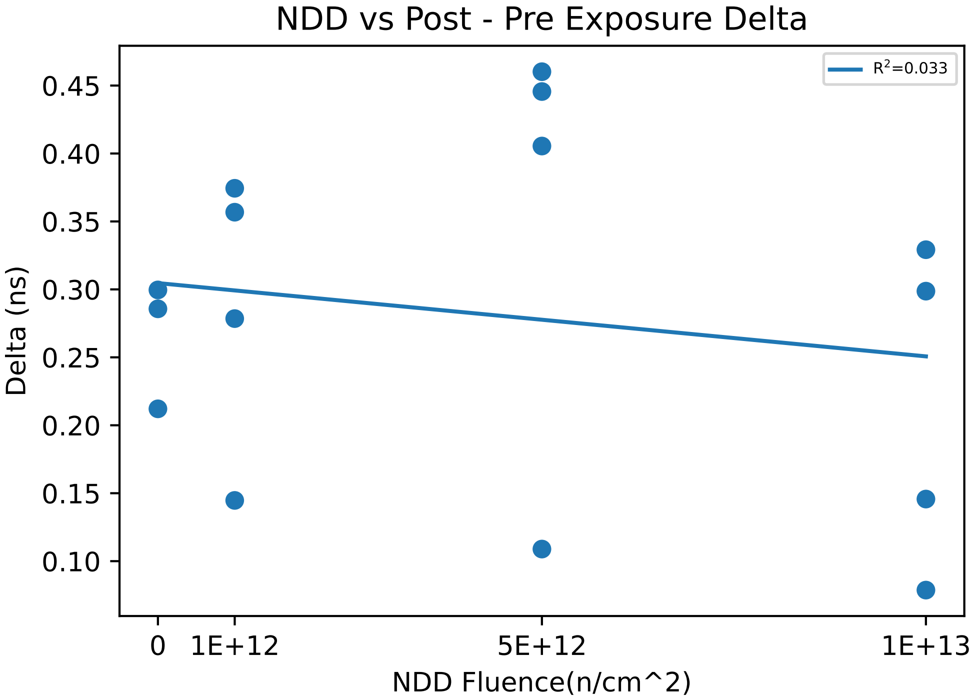
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.6436	3.7776	0.134
2	1e+12	NDD	3.3616	3.3578	-0.0038
3	1e+12	NDD	3.0652	3.0439	-0.0213
4	1e+12	NDD	3.6001	3.6769	0.0768
5	5e+12	NDD	3.2881	3.2476	-0.0405
6	5e+12	NDD	3.3529	3.4697	0.1168
7	5e+12	NDD	3.4438	3.4923	0.0485
8	5e+12	NDD	3.5353	3.4675	-0.0678
9	1e+13	NDD	3.2869	3.3274	0.0405
10	1e+13	NDD	3.6289	3.585	-0.0439
11	1e+13	NDD	3.4163	3.2972	-0.1191
12	1e+13	NDD	3.3356	3.3593	0.0237
13	0	CORRELATION	3.5331	3.5643	0.0312
14	0	CORRELATION	3.2093	3.1808	-0.0285
15	0	CORRELATION	3.1293	3.3165	0.1872

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1293	3.2906	3.5331	0.21381	3.1808	3.3539	3.5643	0.19446	-0.0285	0.0633	0.1872	0.11138
1e+12	3.0652	3.4176	3.6436	0.26565	3.0439	3.464	3.7776	0.33238	-0.0213	0.046425	0.134	0.072345
5e+12	3.2881	3.405	3.5353	0.1078	3.2476	3.4193	3.4923	0.115	-0.0678	0.01425	0.1168	0.084497
1e+13	3.2869	3.4169	3.6289	0.15106	3.2972	3.3922	3.585	0.13099	-0.1191	-0.0247	0.0405	0.072741

Device Test: 24.27 TIMING|OUT_RISE/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_RISE_220PF





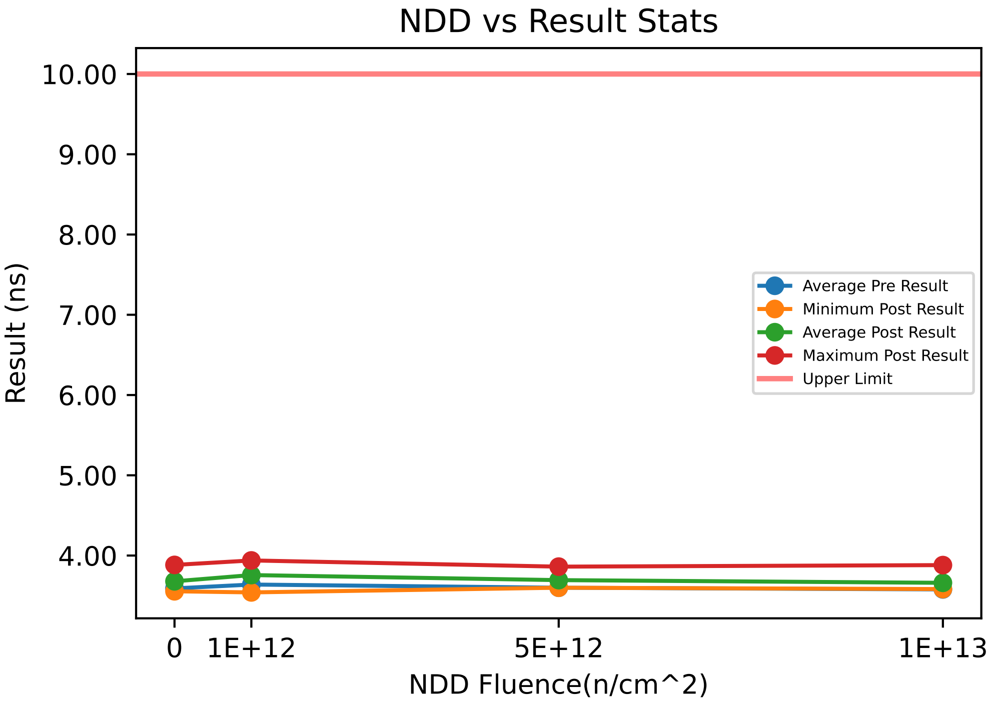
Test Results (Upper Limit = 12.0 (ns))

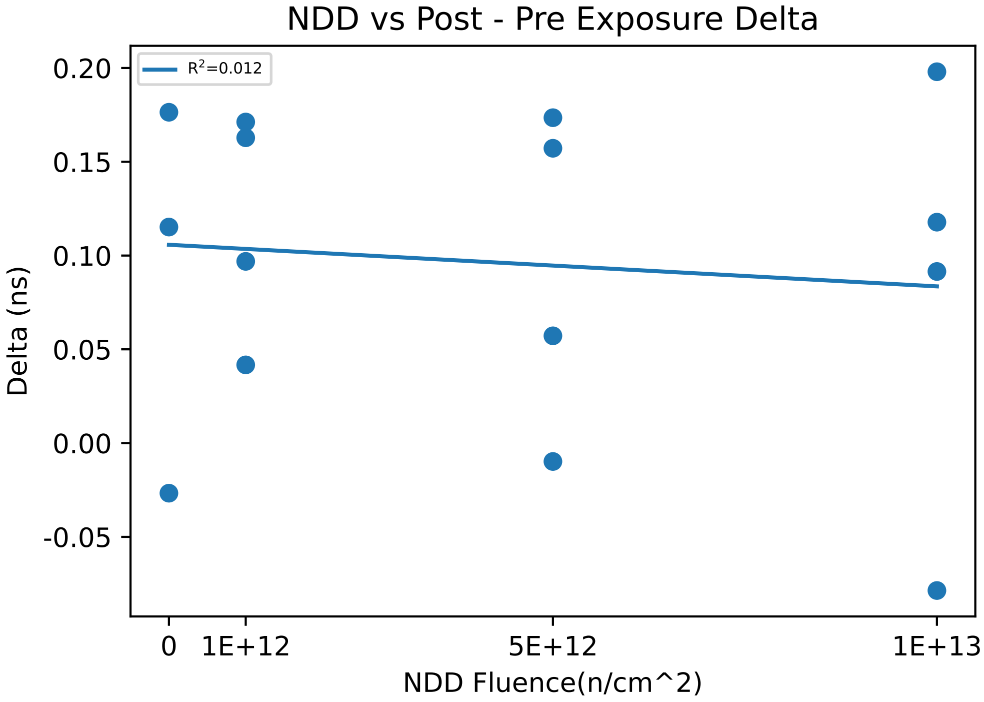
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	4.1059	4.4803	0.3744
2	1e+12	NDD	4.2869	4.4316	0.1447
3	1e+12	NDD	4.272	4.5505	0.2785
4	1e+12	NDD	4.1195	4.4763	0.3568
5	5e+12	NDD	3.9526	4.4128	0.4602
6	5e+12	NDD	4.0577	4.5033	0.4456
7	5e+12	NDD	4.1665	4.572	0.4055
8	5e+12	NDD	4.2401	4.349	0.1089
9	1e+13	NDD	4.2425	4.5717	0.3292
10	1e+13	NDD	4.2154	4.5141	0.2987
11	1e+13	NDD	4.1698	4.3155	0.1457
12	1e+13	NDD	4.4137	4.4924	0.0787
13	0	CORRELATION	4.2739	4.5596	0.2857
14	0	CORRELATION	4.0997	4.3993	0.2996
15	0	CORRELATION	4.2984	4.5105	0.2121

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0997	4.224	4.2984	0.10834	4.3993	4.4898	4.5596	0.08213	0.2121	0.2658	0.2996	0.047022
1e+12	4.1059	4.1961	4.2869	0.096625	4.4316	4.4847	4.5505	0.049123	0.1447	0.2886	0.3744	0.1046
5e+12	3.9526	4.1042	4.2401	0.12582	4.349	4.4593	4.572	0.098261	0.1089	0.35505	0.4602	0.16572
1e+13	4.1698	4.2603	4.4137	0.10654	4.3155	4.4734	4.5717	0.11047	0.0787	0.21307	0.3292	0.1203

Device Test: 24.28 TIMING|OUT_FALL/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_FALL_220PF





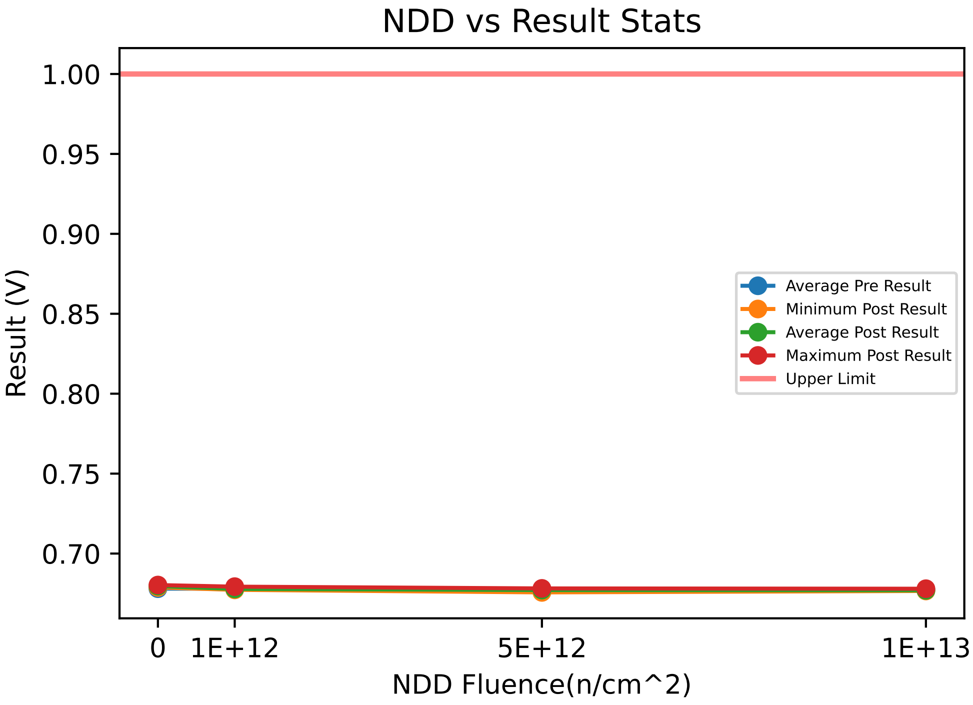
Test Results (Upper Limit = 10.0 (ns))

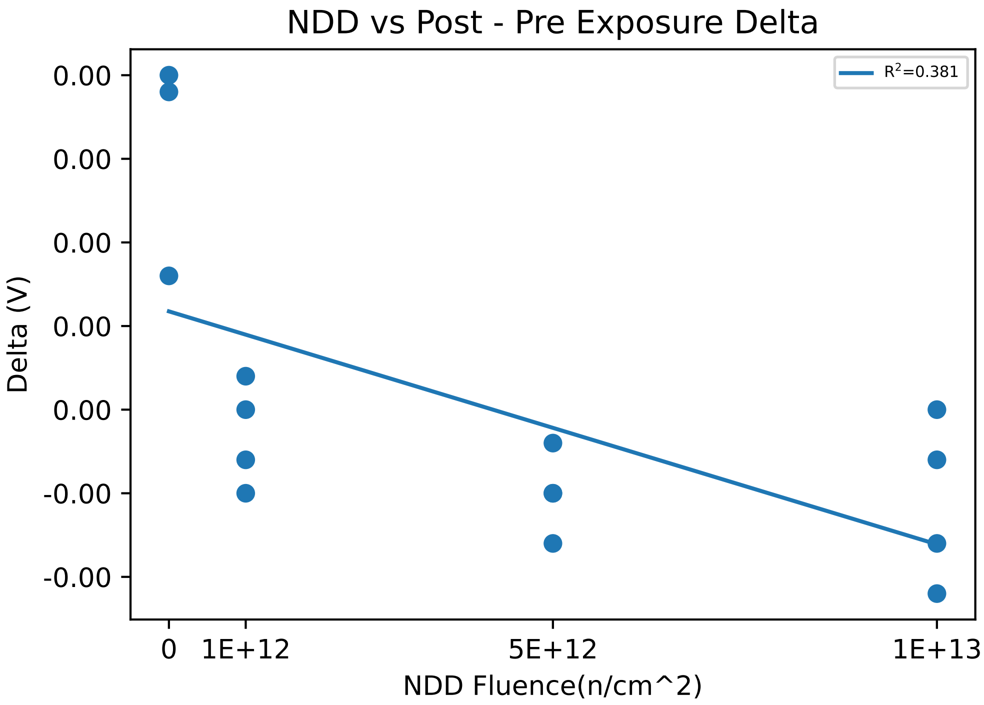
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	3.7761	3.9389	0.1628
2	1e+12	NDD	3.5941	3.6358	0.0417
3	1e+12	NDD	3.4439	3.5408	0.0969
4	1e+12	NDD	3.7405	3.9117	0.1712
5	5e+12	NDD	3.5419	3.5991	0.0572
6	5e+12	NDD	3.457	3.6305	0.1735
7	5e+12	NDD	3.7046	3.8618	0.1572
8	5e+12	NDD	3.6933	3.6835	-0.0098
9	1e+13	NDD	3.4685	3.5863	0.1178
10	1e+13	NDD	3.6828	3.8808	0.198
11	1e+13	NDD	3.6701	3.5915	-0.0786
12	1e+13	NDD	3.4907	3.5822	0.0915
13	0	CORRELATION	3.7679	3.8831	0.1152
14	0	CORRELATION	3.5813	3.5546	-0.0267
15	0	CORRELATION	3.4227	3.5991	0.1764

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.4227	3.5906	3.7679	0.17279	3.5546	3.6789	3.8831	0.17821	-0.0267	0.0883	0.1764	0.10419
1e+12	3.4439	3.6387	3.7761	0.15185	3.5408	3.7568	3.9389	0.19871	0.0417	0.11815	0.1712	0.060839
5e+12	3.457	3.5992	3.7046	0.12037	3.5991	3.6937	3.8618	0.11734	-0.0098	0.094525	0.1735	0.086491
1e+13	3.4685	3.578	3.6828	0.11413	3.5822	3.6602	3.8808	0.14712	-0.0786	0.082175	0.198	0.11636

Device Test: 24.29 VOLTAGE|OUT_CLAMP/OUTL/0/0/0/0/0/0//@OUT_CLAMP_0V


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

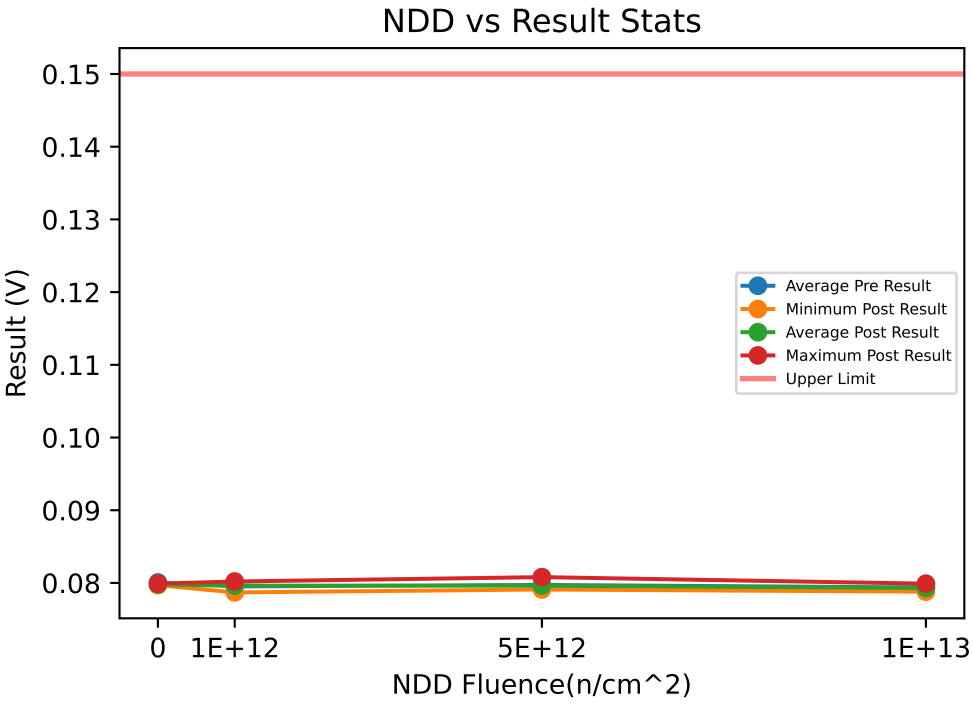
Test Results (Upper Limit = 1.0 (V))

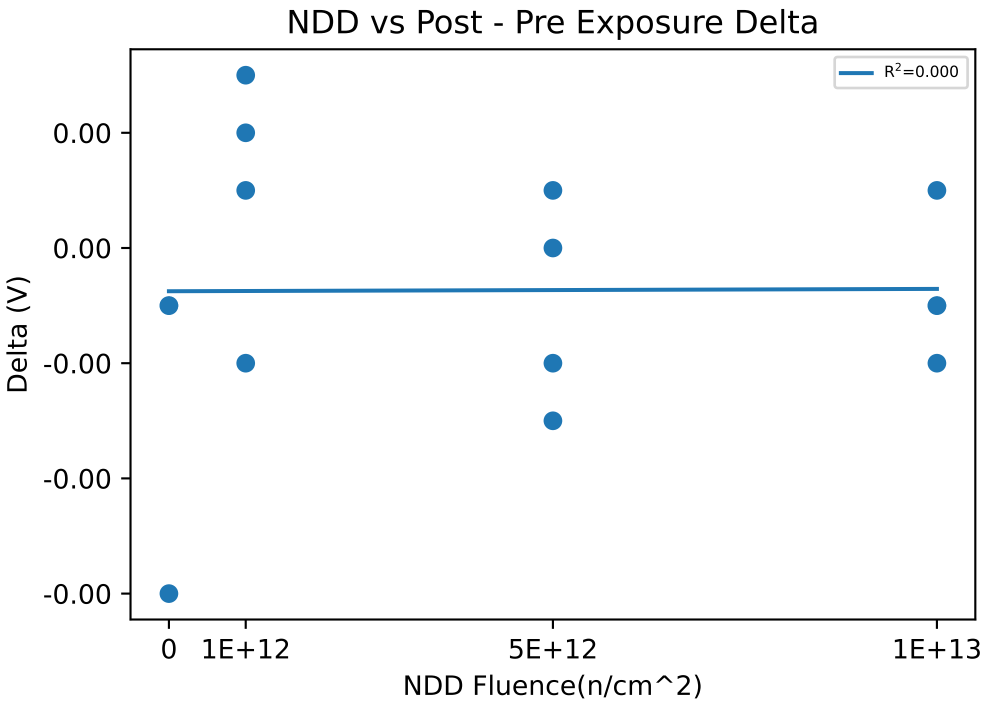
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.6774	0.6776	0.0002
2	1e+12	NDD	0.6776	0.6773	-0.0003
3	1e+12	NDD	0.6798	0.6793	-0.0005
4	1e+12	NDD	0.6773	0.6773	0
5	5e+12	NDD	0.6787	0.6782	-0.0005
6	5e+12	NDD	0.6787	0.6779	-0.0008
7	5e+12	NDD	0.6759	0.6757	-0.0002
8	5e+12	NDD	0.6773	0.6768	-0.0005
9	1e+13	NDD	0.6777	0.6766	-0.0011
10	1e+13	NDD	0.6767	0.6767	0
11	1e+13	NDD	0.6783	0.678	-0.0003
12	1e+13	NDD	0.6775	0.6767	-0.0008
13	0	CORRELATION	0.6778	0.6797	0.0019
14	0	CORRELATION	0.6768	0.6788	0.002
15	0	CORRELATION	0.6795	0.6803	0.0008

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6768	0.67803	0.6795	0.001365	0.6788	0.6796	0.6803	0.00075498	0.0008	0.0015667	0.002	0.00066583
1e+12	0.6773	0.67802	0.6798	0.0011899	0.6773	0.67788	0.6793	0.00096047	-0.0005	-0.00015	0.0002	0.00031091
5e+12	0.6759	0.67765	0.6787	0.0013404	0.6757	0.67715	0.6782	0.0011387	-0.0008	-0.0005	-0.0002	0.00024495
1e+13	0.6767	0.67755	0.6783	0.00066081	0.6766	0.677	0.678	0.00066833	-0.0011	-0.00055	0	0.00049329

Device Test: 24.3 LEVEL|LOW_LEVEL/OUTL/5/5/0/0/5/500kHz//@OUT_VOL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

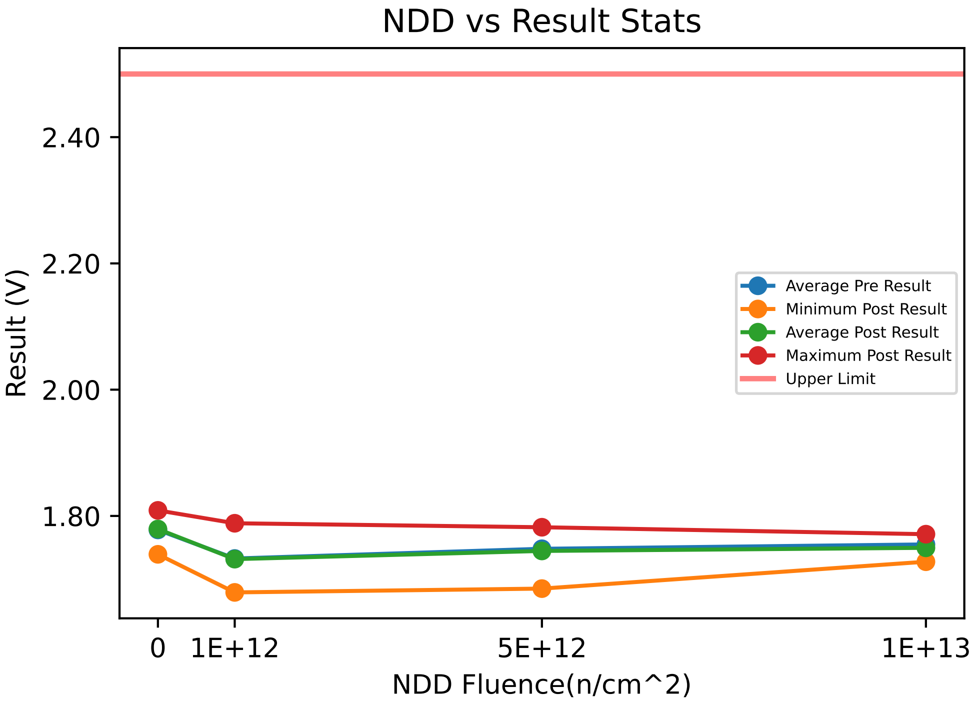
Test Results (Upper Limit = 0.15 (V))

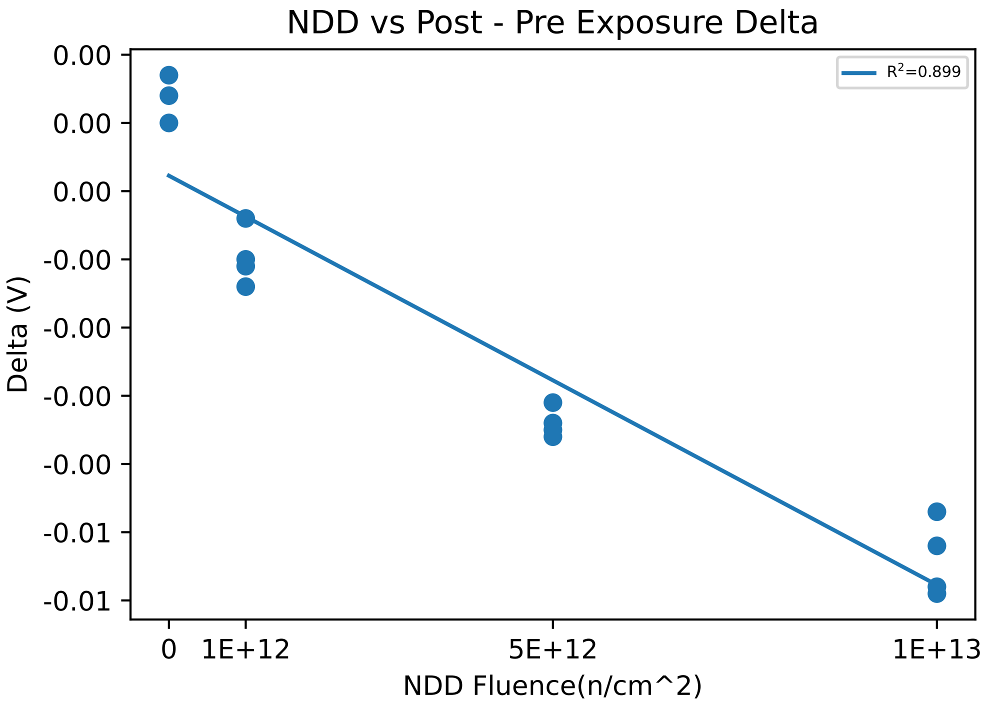
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0784	0.0787	0.0003
2	1e+12	NDD	0.0804	0.0802	-0.0002
3	1e+12	NDD	0.0795	0.0797	0.0002
4	1e+12	NDD	0.0798	0.0799	0.0001
5	5e+12	NDD	0.0794	0.0791	-0.0003
6	5e+12	NDD	0.0792	0.0792	0
7	5e+12	NDD	0.0807	0.0808	0.0001
8	5e+12	NDD	0.0796	0.0794	-0.0002
9	1e+13	NDD	0.0789	0.0788	-0.0001
10	1e+13	NDD	0.0798	0.0799	0.0001
11	1e+13	NDD	0.0798	0.0796	-0.0002
12	1e+13	NDD	0.079	0.0789	-0.0001
13	0	CORRELATION	0.08	0.0799	-0.0001
14	0	CORRELATION	0.0804	0.0798	-0.0006
15	0	CORRELATION	0.0798	0.0797	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0798	0.080067	0.0804	0.00030551	0.0797	0.0798	0.0799	0.0001	-0.0006	-0.00026667	-0.0001	0.00028868
1e+12	0.0784	0.079525	0.0804	0.00083815	0.0787	0.079625	0.0802	0.00065	-0.0002	0.0001	0.0003	0.00021602
5e+12	0.0792	0.079725	0.0807	0.0006702	0.0791	0.079625	0.0808	0.0007932	-0.0003	-0.0001	0.0001	0.00018257
1e+13	0.0789	0.079375	0.0798	0.00049244	0.0788	0.0793	0.0799	0.00053541	-0.0002	-7.5e-05	0.0001	0.00012583

Device Test: 24.30 VOLTAGE|OUT_CLAMP/OUTL/5/0/0/0/0/0//@OUT_CLAMP_FULL


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

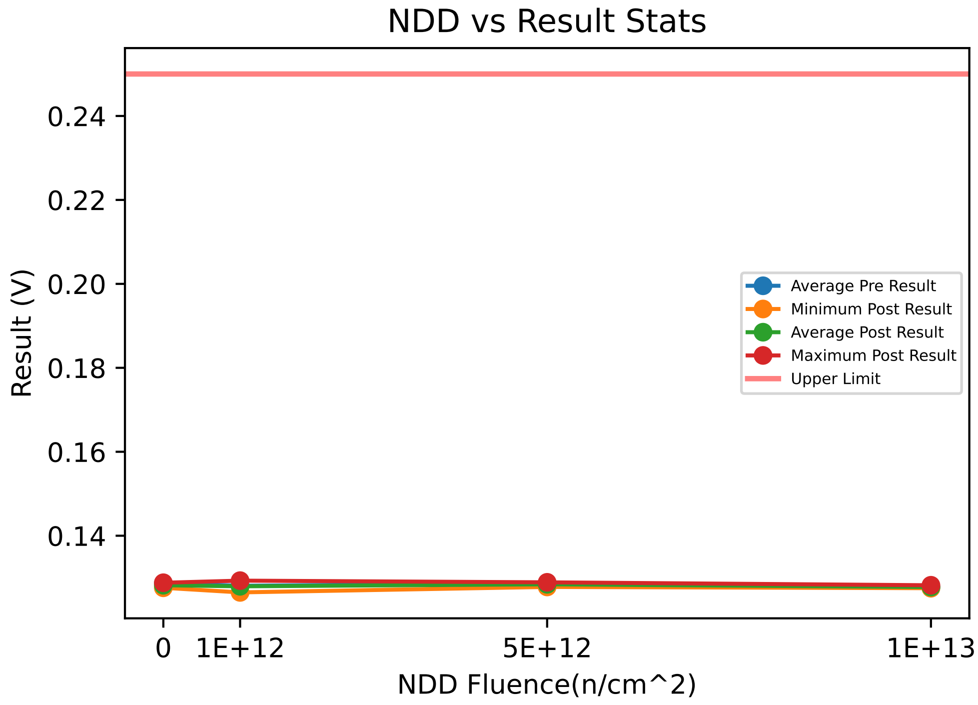
Test Results (Upper Limit = 2.5 (V))

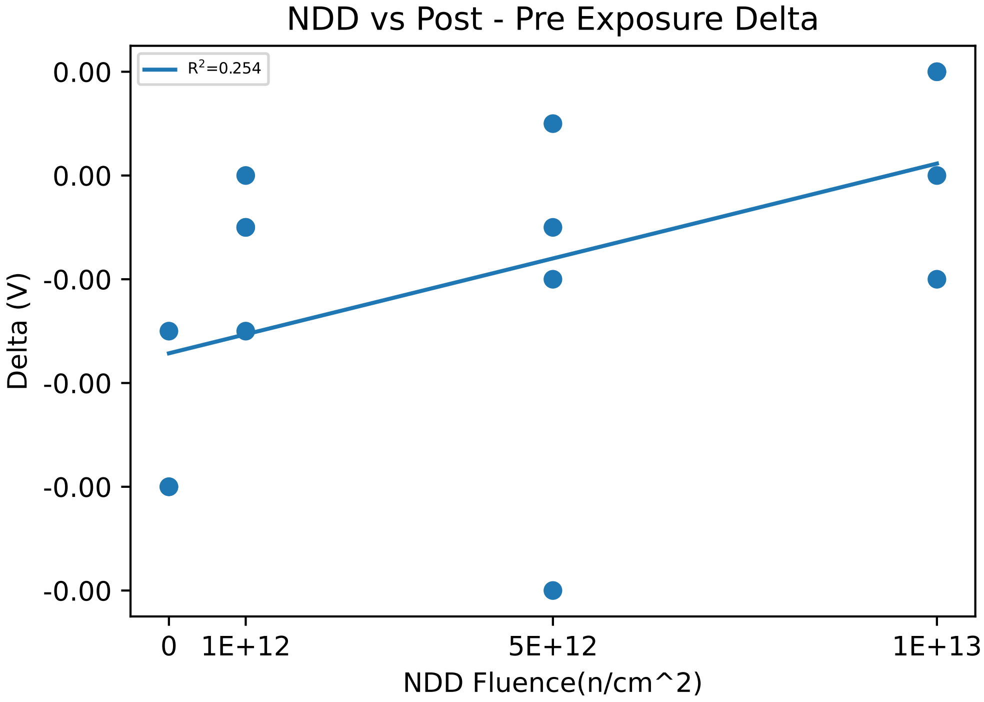
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.6793	1.6789	-0.0004
2	1e+12	NDD	1.7228	1.7214	-0.0014
3	1e+12	NDD	1.7895	1.7884	-0.0011
4	1e+12	NDD	1.7387	1.7377	-0.001
5	5e+12	NDD	1.7856	1.7821	-0.0035
6	5e+12	NDD	1.7479	1.7445	-0.0034
7	5e+12	NDD	1.7699	1.7668	-0.0031
8	5e+12	NDD	1.6885	1.6849	-0.0036
9	1e+13	NDD	1.7476	1.7418	-0.0058
10	1e+13	NDD	1.7322	1.7275	-0.0047
11	1e+13	NDD	1.7763	1.7711	-0.0052
12	1e+13	NDD	1.7635	1.7576	-0.0059
13	0	CORRELATION	1.7375	1.7392	0.0017
14	0	CORRELATION	1.8074	1.8088	0.0014
15	0	CORRELATION	1.7888	1.7898	0.001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7375	1.7779	1.8074	0.036202	1.7392	1.7793	1.8088	0.035976	0.001	0.0013667	0.0017	0.00035119
1e+12	1.6793	1.7326	1.7895	0.045504	1.6789	1.7316	1.7884	0.045258	-0.0014	-0.000975	-0.0004	0.00041932
5e+12	1.6885	1.748	1.7856	0.042558	1.6849	1.7446	1.7821	0.042674	-0.0036	-0.0034	-0.0031	0.00021602
1e+13	1.7322	1.7549	1.7763	0.019153	1.7275	1.7495	1.7711	0.018934	-0.0059	-0.0054	-0.0047	0.00055976

Device Test: 24.4 LEVEL|HIGH_LEVEL/OUTH/5/5/0/0/5/500kHz//@OUT_VOH





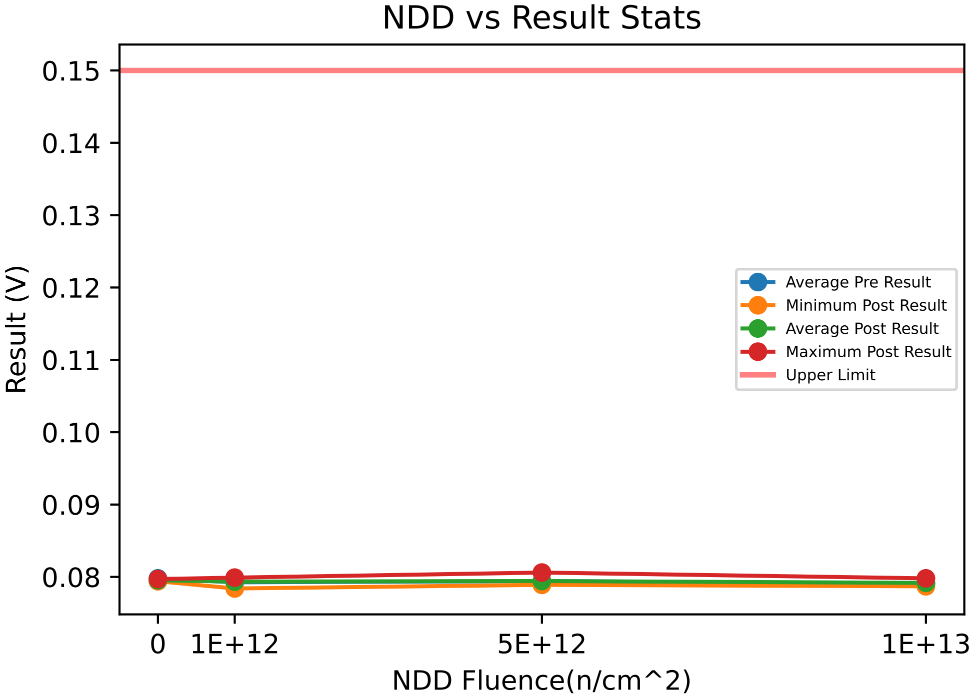
Test Results (Upper Limit = 0.25 (V))

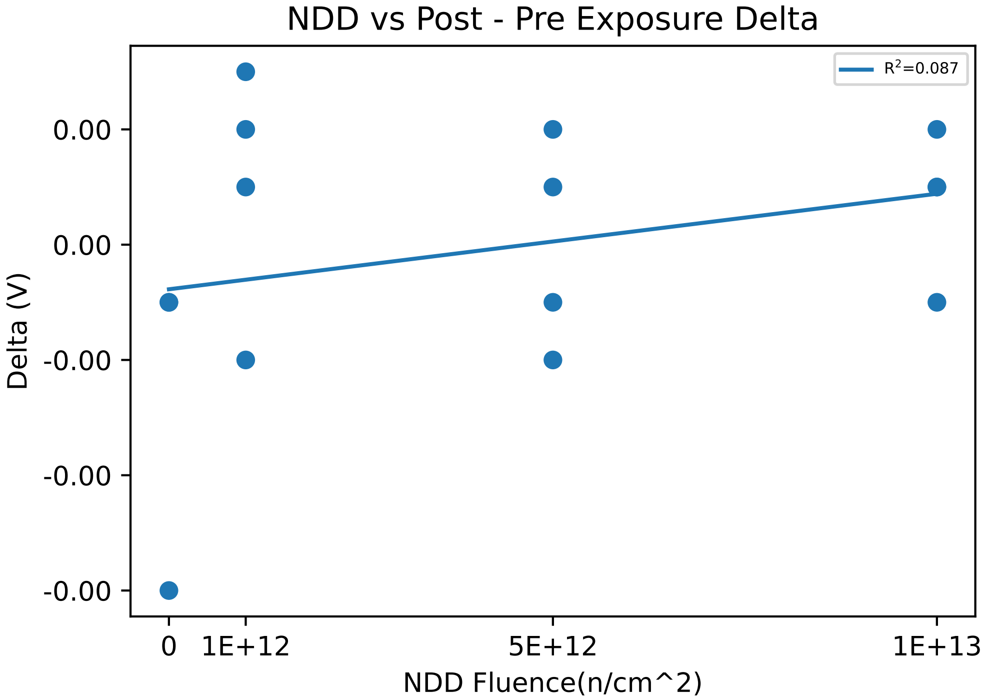
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1266	0.1265	-0.0001
2	1e+12	NDD	0.1288	0.1287	-0.0001
3	1e+12	NDD	0.1293	0.1293	0
4	1e+12	NDD	0.1276	0.1273	-0.0003
5	5e+12	NDD	0.1291	0.1283	-0.0008
6	5e+12	NDD	0.1277	0.1278	0.0001
7	5e+12	NDD	0.1291	0.1289	-0.0002
8	5e+12	NDD	0.1288	0.1287	-0.0001
9	1e+13	NDD	0.1276	0.1278	0.0002
10	1e+13	NDD	0.1278	0.1276	-0.0002
11	1e+13	NDD	0.1282	0.1282	0
12	1e+13	NDD	0.1273	0.1275	0.0002
13	0	CORRELATION	0.1282	0.1276	-0.0006
14	0	CORRELATION	0.1288	0.1282	-0.0006
15	0	CORRELATION	0.1291	0.1288	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1282	0.1287	0.1291	0.00045826	0.1276	0.1282	0.1288	0.0006	-0.0006	-0.0005	-0.0003	0.00017321
1e+12	0.1266	0.12807	0.1293	0.0012148	0.1265	0.12795	0.1293	0.0012793	-0.0003	-0.000125	0	0.00012583
5e+12	0.1277	0.12867	0.1291	0.00066521	0.1278	0.12843	0.1289	0.00048563	-0.0008	-0.00025	0.0001	0.0003873
1e+13	0.1273	0.12773	0.1282	0.00037749	0.1275	0.12777	0.1282	0.00030957	-0.0002	5e-05	0.0002	0.00019149

Device Test: 24.5 LEVEL|LOW_LEVEL/OUTL/12/12/0/0/5/500kHz//@OUT_VOL





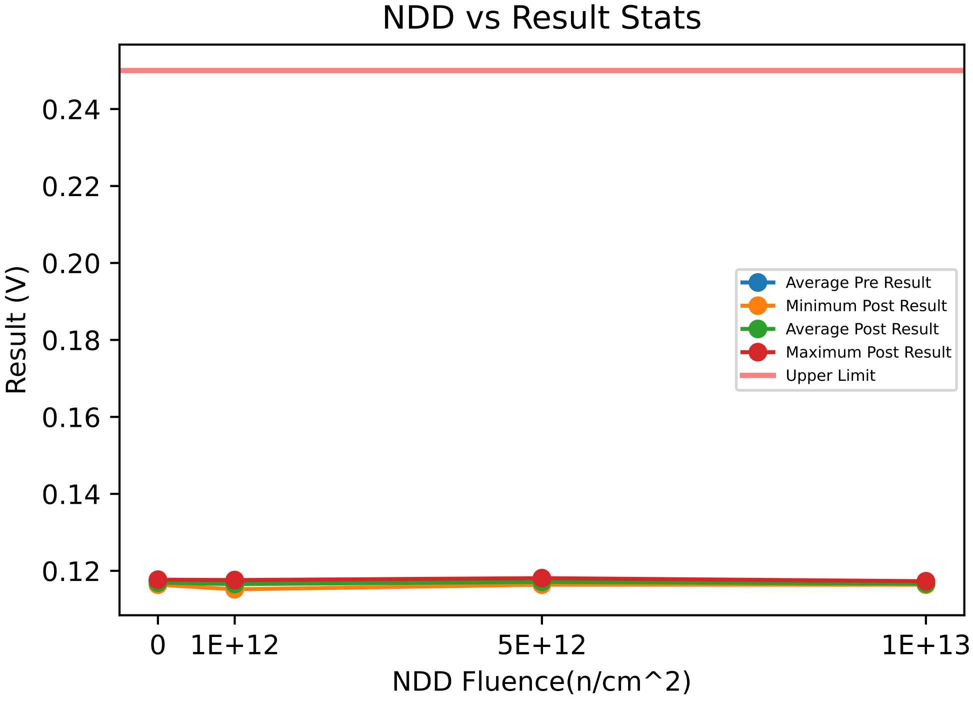
Test Results (Upper Limit = 0.15 (V))

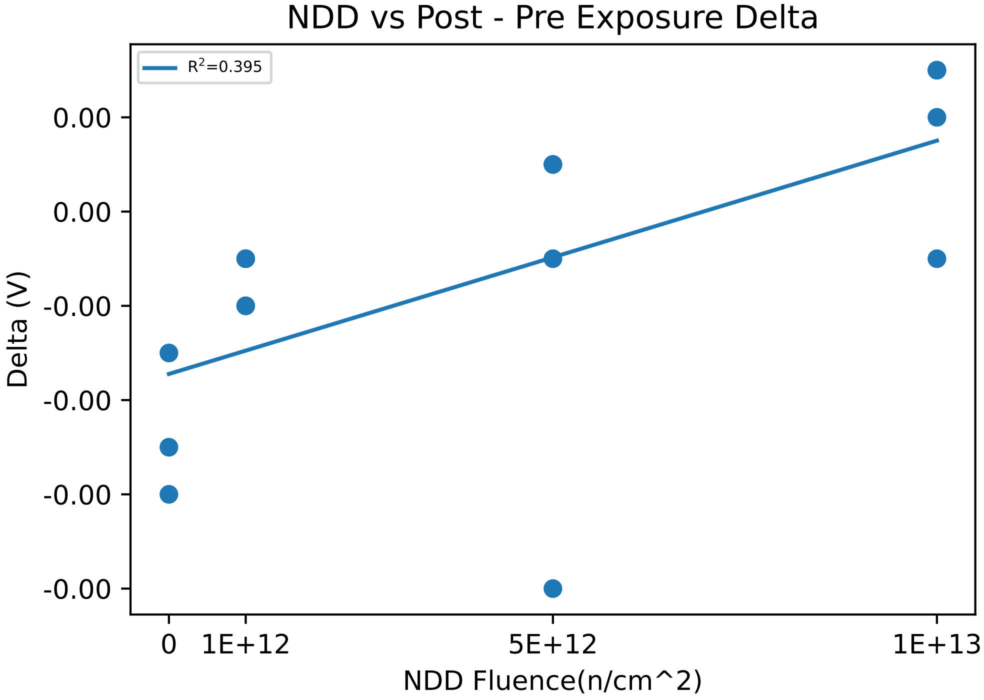
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0781	0.0784	0.0003
2	1e+12	NDD	0.0801	0.0799	-0.0002
3	1e+12	NDD	0.0793	0.0794	0.0001
4	1e+12	NDD	0.0795	0.0797	0.0002
5	5e+12	NDD	0.0791	0.0789	-0.0002
6	5e+12	NDD	0.0789	0.079	0.0001
7	5e+12	NDD	0.0804	0.0806	0.0002
8	5e+12	NDD	0.0793	0.0792	-0.0001
9	1e+13	NDD	0.0787	0.0788	0.0001
10	1e+13	NDD	0.0796	0.0798	0.0002
11	1e+13	NDD	0.0795	0.0794	-0.0001
12	1e+13	NDD	0.0786	0.0787	0.0001
13	0	CORRELATION	0.0798	0.0797	-0.0001
14	0	CORRELATION	0.0801	0.0795	-0.0006
15	0	CORRELATION	0.0795	0.0794	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0795	0.0798	0.0801	0.0003	0.0794	0.079533	0.0797	0.00015275	-0.0006	-0.00026667	-0.0001	0.00028868
1e+12	0.0781	0.07925	0.0801	0.00083865	0.0784	0.07935	0.0799	0.00066583	-0.0002	0.0001	0.0003	0.00021602
5e+12	0.0789	0.079425	0.0804	0.0006702	0.0789	0.079425	0.0806	0.0007932	-0.0002	3.4694e-18	0.0002	0.00018257
1e+13	0.0786	0.0791	0.0796	0.00052281	0.0787	0.079175	0.0798	0.00051881	-0.0001	7.5e-05	0.0002	0.00012583

Device Test: 24.6 LEVEL|HIGH_LEVEL/OUTH/12/12/0/0/5/500kHz//@OUT_VOH





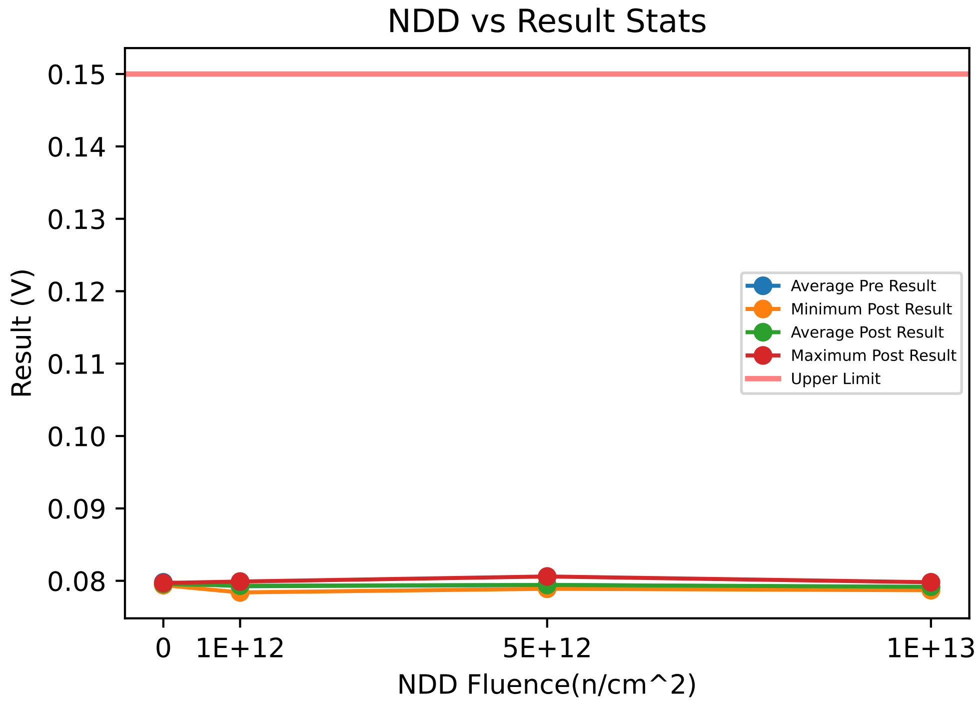
Test Results (Upper Limit = 0.25 (V))

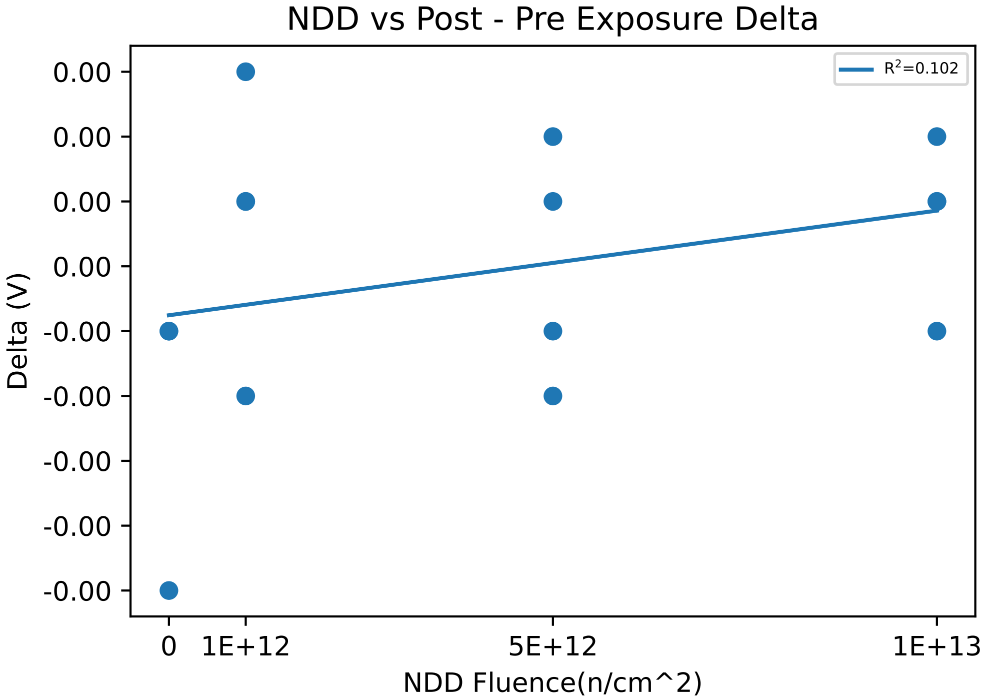
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1154	0.1152	-0.0002
2	1e+12	NDD	0.1175	0.1174	-0.0001
3	1e+12	NDD	0.1177	0.1176	-0.0001
4	1e+12	NDD	0.1162	0.116	-0.0002
5	5e+12	NDD	0.1172	0.1164	-0.0008
6	5e+12	NDD	0.1164	0.1165	0.0001
7	5e+12	NDD	0.1176	0.1175	-0.0001
8	5e+12	NDD	0.118	0.1181	0.0001
9	1e+13	NDD	0.1161	0.1164	0.0003
10	1e+13	NDD	0.1165	0.1164	-0.0001
11	1e+13	NDD	0.1171	0.1173	0.0002
12	1e+13	NDD	0.1163	0.1166	0.0003
13	0	CORRELATION	0.1169	0.1164	-0.0005
14	0	CORRELATION	0.1173	0.1167	-0.0006
15	0	CORRELATION	0.118	0.1177	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1169	0.1174	0.118	0.00055678	0.1164	0.11693	0.1177	0.00068069	-0.0006	-0.00046667	-0.0003	0.00015275
1e+12	0.1154	0.1167	0.1177	0.0010924	0.1152	0.11655	0.1176	0.0011475	-0.0002	-0.00015	-0.0001	5.7735e-05
5e+12	0.1164	0.1173	0.118	0.00068313	0.1164	0.11713	0.1181	0.00081803	-0.0008	-0.000175	0.0001	0.0004272
1e+13	0.1161	0.1165	0.1171	0.00043205	0.1164	0.11668	0.1173	0.0004272	-0.0001	0.000175	0.0003	0.0001893

Device Test: 24.7 LEVEL|LOW_LEVEL/OUTL/14/14/0/0/5/500kHz//@OUT_VOL





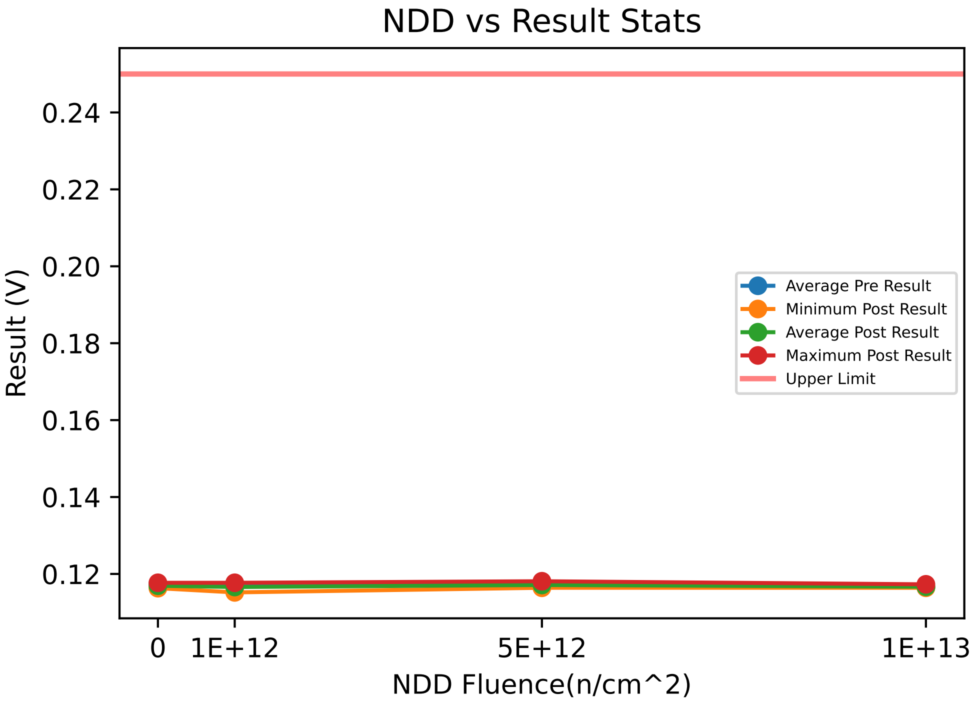
Test Results (Upper Limit = 0.15 (V))

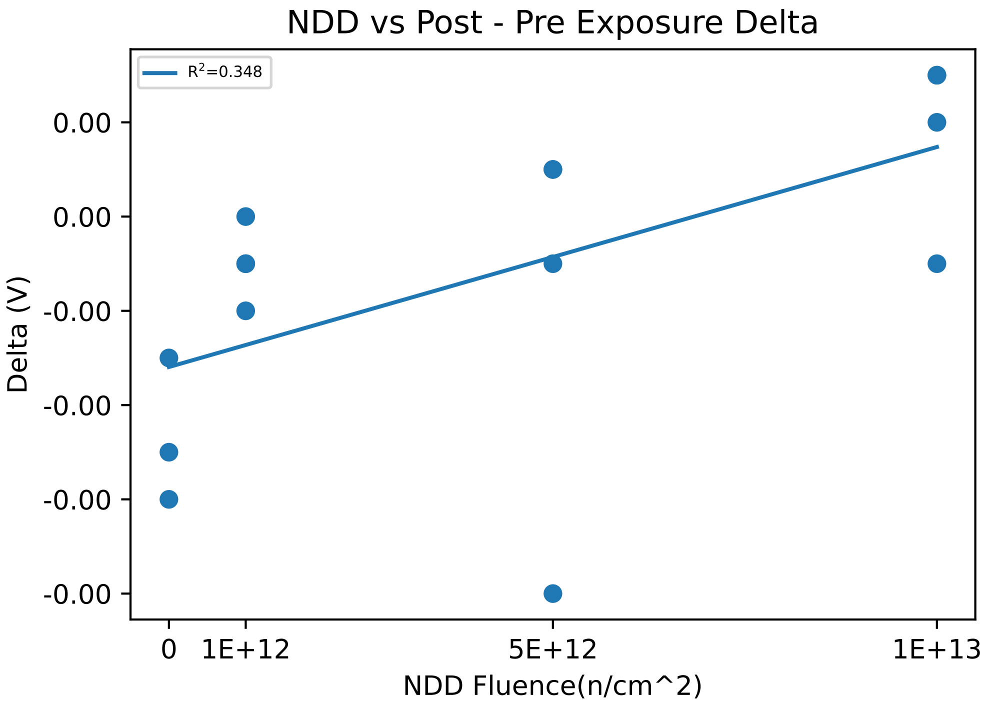
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.0781	0.0784	0.0003
2	1e+12	NDD	0.0801	0.0799	-0.0002
3	1e+12	NDD	0.0793	0.0794	0.0001
4	1e+12	NDD	0.0795	0.0796	0.0001
5	5e+12	NDD	0.0791	0.0789	-0.0002
6	5e+12	NDD	0.0789	0.079	0.0001
7	5e+12	NDD	0.0804	0.0806	0.0002
8	5e+12	NDD	0.0793	0.0792	-0.0001
9	1e+13	NDD	0.0787	0.0788	0.0001
10	1e+13	NDD	0.0796	0.0798	0.0002
11	1e+13	NDD	0.0795	0.0794	-0.0001
12	1e+13	NDD	0.0786	0.0787	0.0001
13	0	CORRELATION	0.0798	0.0797	-0.0001
14	0	CORRELATION	0.0801	0.0796	-0.0005
15	0	CORRELATION	0.0795	0.0794	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0795	0.0798	0.0801	0.0003	0.0794	0.079567	0.0797	0.00015275	-0.0005	-0.00023333	-0.0001	0.00023094
1e+12	0.0781	0.07925	0.0801	0.00083865	0.0784	0.079325	0.0799	0.00065	-0.0002	7.5e-05	0.0003	0.00020616
5e+12	0.0789	0.079425	0.0804	0.0006702	0.0789	0.079425	0.0806	0.0007932	-0.0002	3.4694e-18	0.0002	0.00018257
1e+13	0.0786	0.0791	0.0796	0.00052281	0.0787	0.079175	0.0798	0.00051881	-0.0001	7.5e-05	0.0002	0.00012583

Device Test: 24.8 LEVEL|HIGH_LEVEL/OUTH/14/14/0/0/5/500kHz//@OUT_VOH





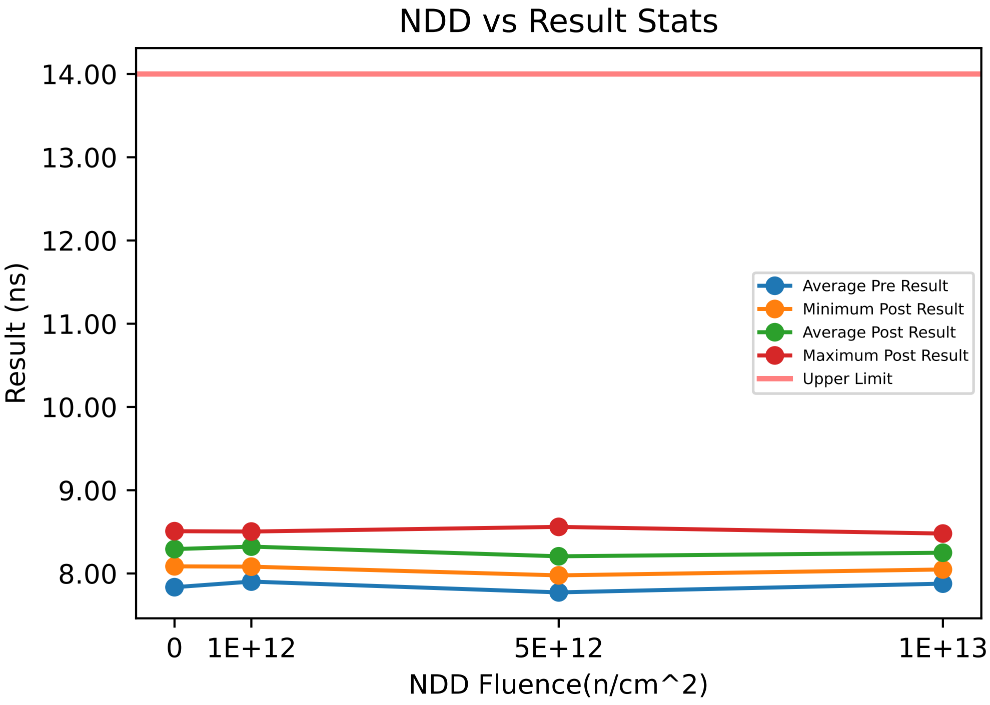
Test Results (Upper Limit = 0.25 (V))

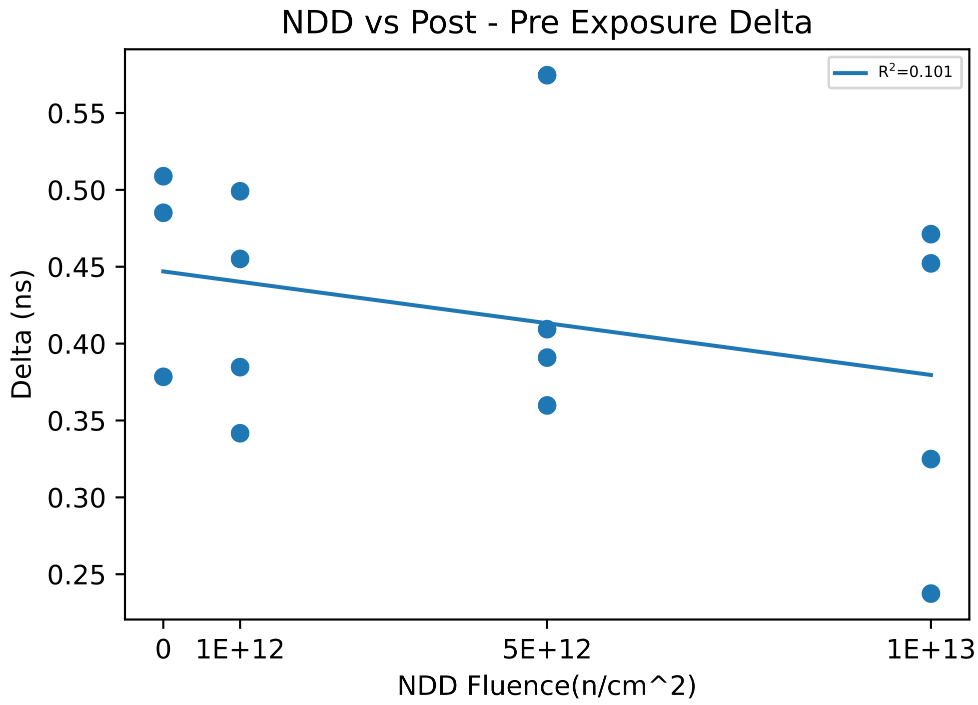
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.1153	0.1152	-0.0001
2	1e+12	NDD	0.1176	0.1175	-0.0001
3	1e+12	NDD	0.1177	0.1177	0
4	1e+12	NDD	0.1162	0.116	-0.0002
5	5e+12	NDD	0.1172	0.1164	-0.0008
6	5e+12	NDD	0.1164	0.1165	0.0001
7	5e+12	NDD	0.1176	0.1175	-0.0001
8	5e+12	NDD	0.118	0.1181	0.0001
9	1e+13	NDD	0.1161	0.1164	0.0003
10	1e+13	NDD	0.1165	0.1164	-0.0001
11	1e+13	NDD	0.1171	0.1173	0.0002
12	1e+13	NDD	0.1163	0.1166	0.0003
13	0	CORRELATION	0.1169	0.1163	-0.0006
14	0	CORRELATION	0.1173	0.1168	-0.0005
15	0	CORRELATION	0.118	0.1177	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1169	0.1174	0.118	0.00055678	0.1163	0.11693	0.1177	0.00070946	-0.0006	-0.00046667	-0.0003	0.00015275
1e+12	0.1153	0.1167	0.1177	0.0011576	0.1152	0.1166	0.1177	0.0012028	-0.0002	-0.0001	0	8.165e-05
5e+12	0.1164	0.1173	0.118	0.00068313	0.1164	0.11713	0.1181	0.00081803	-0.0008	-0.000175	0.0001	0.0004272
1e+13	0.1161	0.1165	0.1171	0.00043205	0.1164	0.11668	0.1173	0.0004272	-0.0001	0.000175	0.0003	0.0001893

Device Test: 24.9 TIMING|OUT_RISE/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_RISE_4P5


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

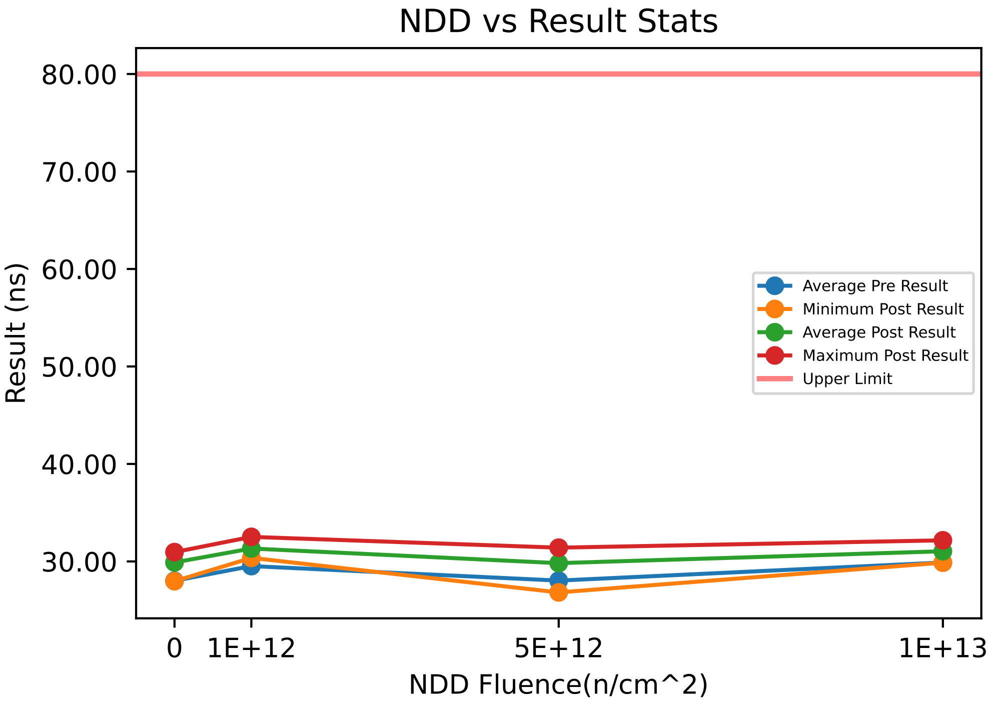
Test Results (Upper Limit = 14.0 (ns))

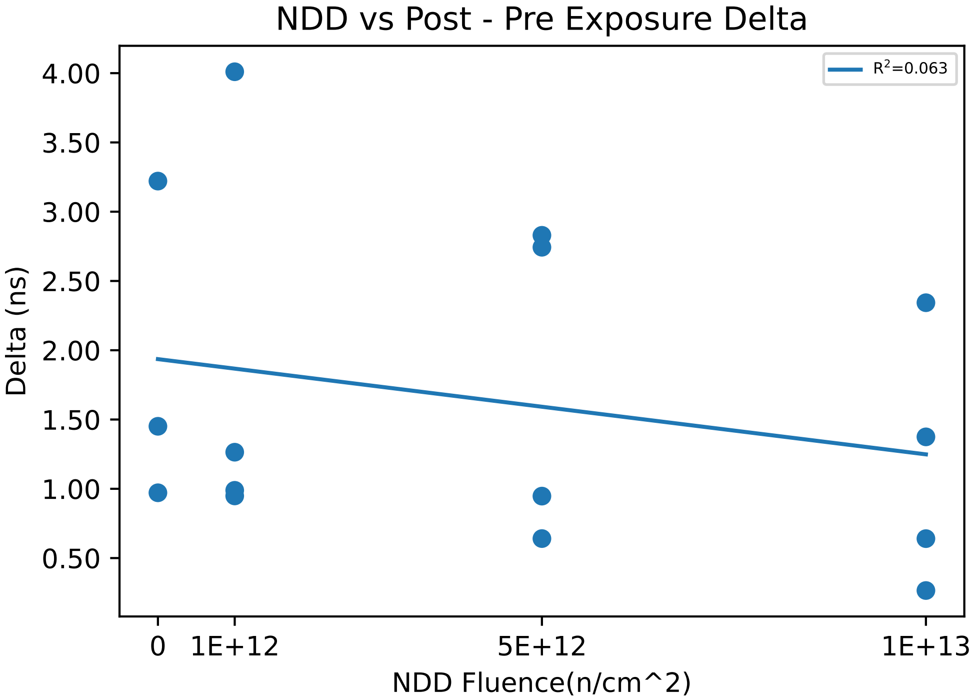
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	8.0951	8.4368	0.3417
2	1e+12	NDD	7.6971	8.0818	0.3847
3	1e+12	NDD	7.7691	8.2682	0.4991
4	1e+12	NDD	8.0487	8.5038	0.4551
5	5e+12	NDD	7.4958	8.0704	0.5746
6	5e+12	NDD	7.8085	8.2179	0.4094
7	5e+12	NDD	8.1999	8.5597	0.3598
8	5e+12	NDD	7.5863	7.9772	0.3909
9	1e+13	NDD	7.7995	8.2517	0.4522
10	1e+13	NDD	8.0084	8.4796	0.4712
11	1e+13	NDD	7.723	8.0479	0.3249
12	1e+13	NDD	7.9796	8.217	0.2374
13	0	CORRELATION	7.999	8.5079	0.5089
14	0	CORRELATION	7.7074	8.0858	0.3784
15	0	CORRELATION	7.7991	8.2842	0.4851

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.7074	7.8352	7.999	0.14911	8.0858	8.2926	8.5079	0.21118	0.3784	0.45747	0.5089	0.0695
1e+12	7.6971	7.9025	8.0951	0.19871	8.0818	8.3226	8.5038	0.1887	0.3417	0.42015	0.4991	0.070393
5e+12	7.4958	7.7726	8.1999	0.31369	7.9772	8.2063	8.5597	0.25559	0.3598	0.43367	0.5746	0.096153
1e+13	7.723	7.8776	8.0084	0.13846	8.0479	8.2491	8.4796	0.17762	0.2374	0.37143	0.4712	0.11046

Device Test: 25.1 TIMING|LEB/EN/5/5/0/0/5/500kHz//@T_LEB


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

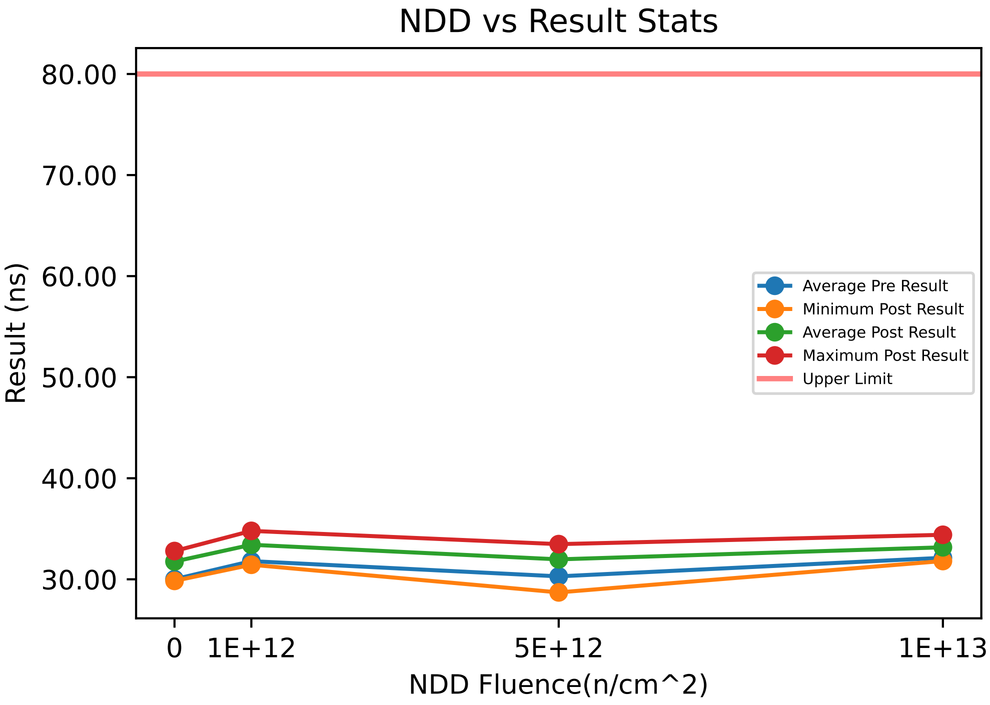
Test Results (Upper Limit = 80.0 (ns))

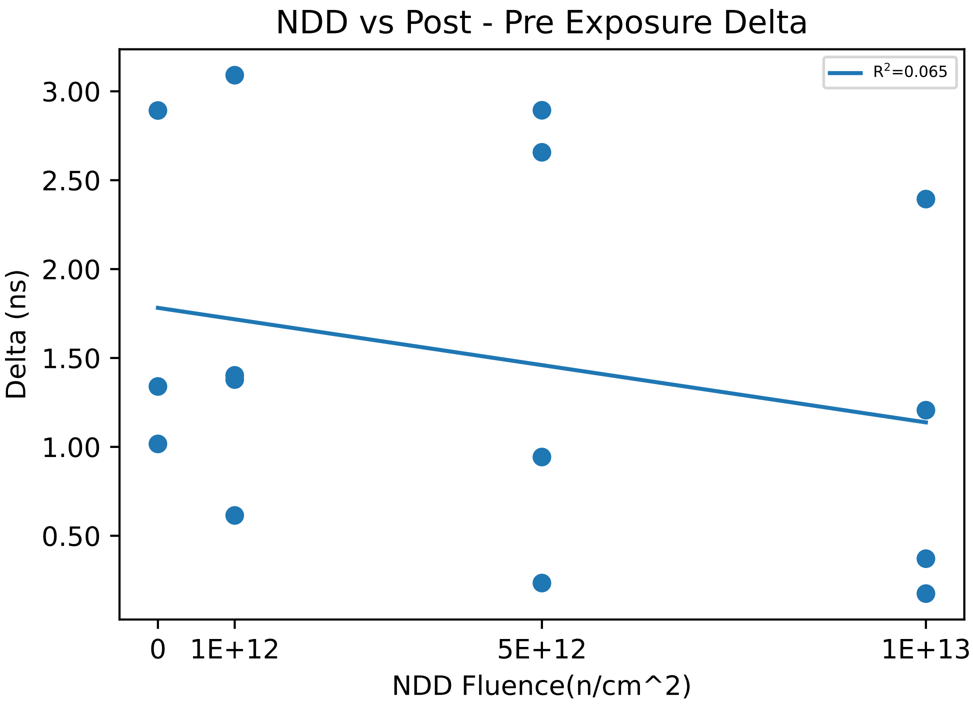
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	30.955	31.903	0.9486
2	1e+12	NDD	26.354	30.364	4.0101
3	1e+12	NDD	31.53	32.519	0.989
4	1e+12	NDD	29.255	30.519	1.2641
5	5e+12	NDD	27.032	29.775	2.7434
6	5e+12	NDD	30.646	31.287	0.6407
7	5e+12	NDD	25.877	26.824	0.9472
8	5e+12	NDD	28.582	31.412	2.8296
9	1e+13	NDD	29.234	29.875	0.6403
10	1e+13	NDD	29.981	31.355	1.3748
11	1e+13	NDD	28.438	30.781	2.3431
12	1e+13	NDD	31.9	32.166	0.2658
13	0	CORRELATION	26.52	27.971	1.4511
14	0	CORRELATION	27.735	30.956	3.2209
15	0	CORRELATION	29.797	30.768	0.9713

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.52	28.017	29.797	1.6565	27.971	29.898	30.956	1.6715	0.9713	1.8811	3.2209	1.1848
1e+12	26.354	29.524	31.53	2.3233	30.364	31.327	32.519	1.0541	0.9486	1.803	4.0101	1.4781
5e+12	25.877	28.034	30.646	2.0639	26.824	29.824	31.412	2.134	0.6407	1.7902	2.8296	1.1577
1e+13	28.438	29.888	31.9	1.4819	29.875	31.044	32.166	0.96476	0.2658	1.156	2.3431	0.91569

Device Test: 25.4 TIMING|LEB/EN/12/12/0/0/5/500kHz//@T_LEB





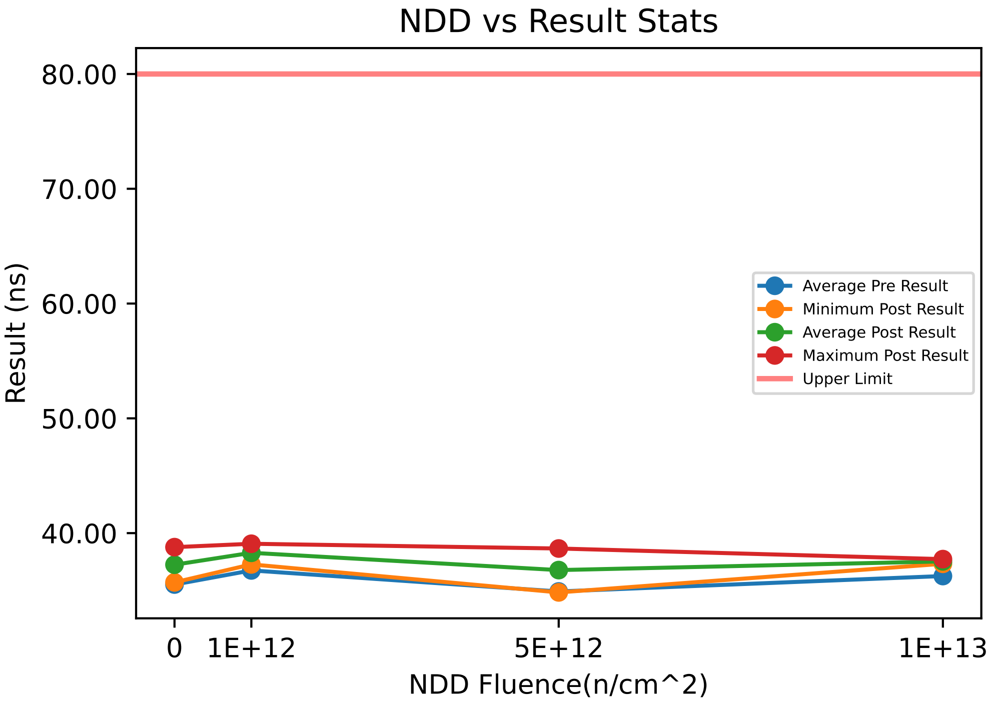
Test Results (Upper Limit = 80.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	33.286	34.688	1.4022
2	1e+12	NDD	28.348	31.439	3.0906
3	1e+12	NDD	34.177	34.791	0.6144
4	1e+12	NDD	31.375	32.754	1.3787
5	5e+12	NDD	29.416	32.309	2.8933
6	5e+12	NDD	33.165	33.399	0.2341
7	5e+12	NDD	27.76	28.703	0.943
8	5e+12	NDD	30.822	33.479	2.6569
9	1e+13	NDD	31.633	31.808	0.1748
10	1e+13	NDD	32.362	33.569	1.2064
11	1e+13	NDD	30.487	32.881	2.3938
12	1e+13	NDD	34.031	34.402	0.3712
13	0	CORRELATION	28.503	29.843	1.3398
14	0	CORRELATION	29.904	32.796	2.892
15	0	CORRELATION	31.613	32.63	1.0167

Test Statistics (ns)

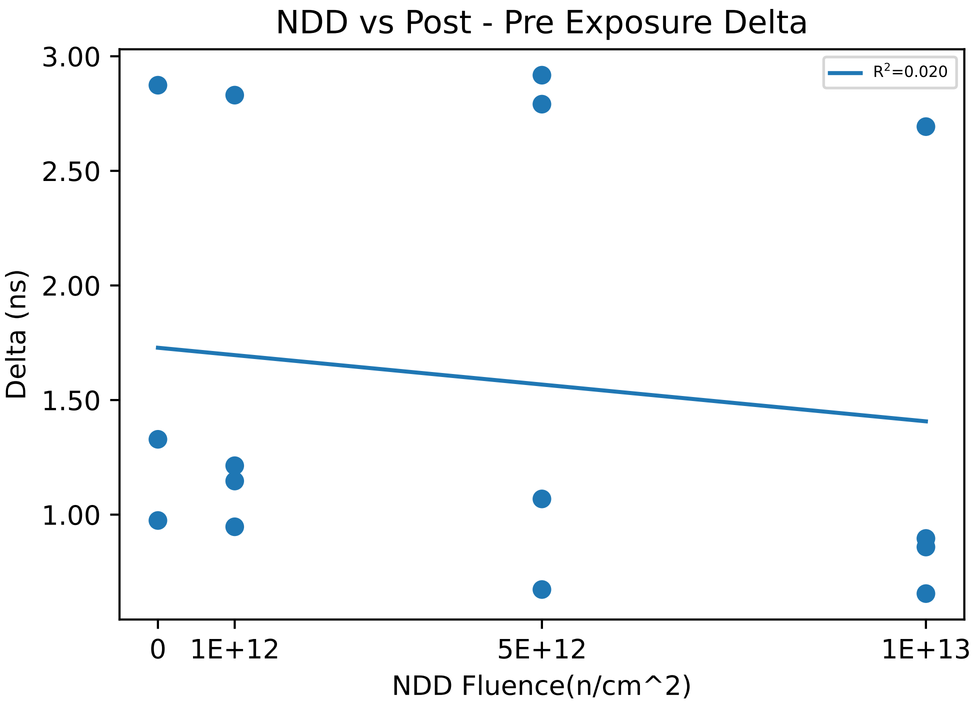
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	28.503	30.007	31.613	1.5577	29.843	31.756	32.796	1.659	1.0167	1.7495	2.892	1.0025
1e+12	28.348	31.796	34.177	2.5789	31.439	33.418	34.791	1.6183	0.6144	1.6215	3.0906	1.0456
5e+12	27.76	30.291	33.165	2.2884	28.703	31.972	33.479	2.2438	0.2341	1.6818	2.8933	1.2987
1e+13	30.487	32.128	34.031	1.4848	31.808	33.165	34.402	1.0978	0.1748	1.0366	2.3938	1.0093

Device Test: 25.7 TIMING|LEB/EN/14/14/0/0/5/500kHz//@T_LEB



Test Results (Upper Limit = 80.0 (ns))

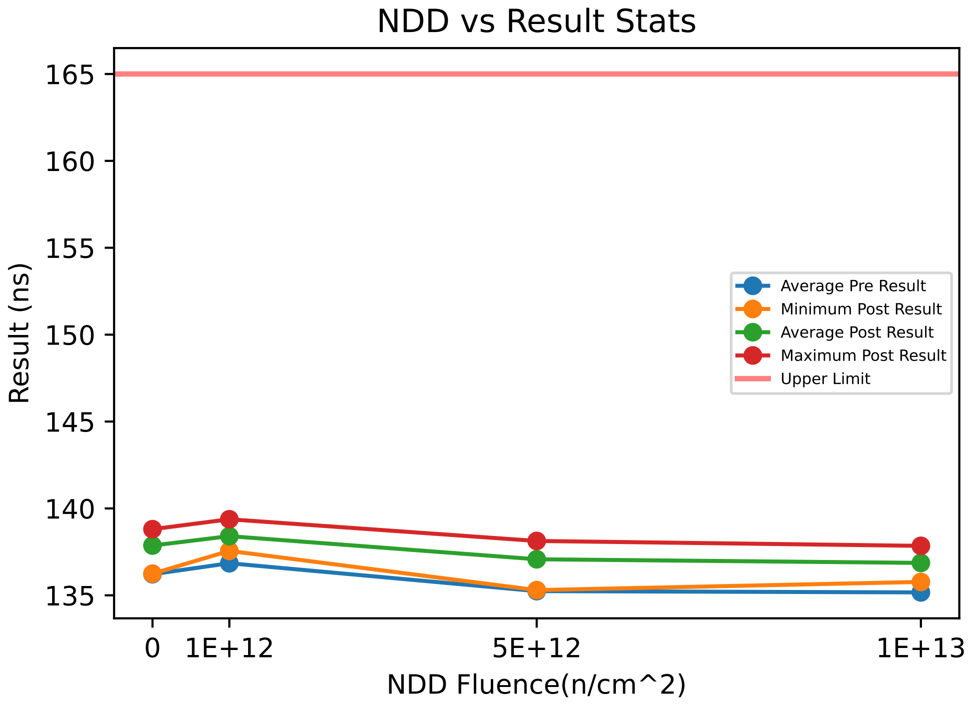
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	37.859	39.073	1.2135
2	1e+12	NDD	34.445	37.275	2.8304
3	1e+12	NDD	37.189	38.136	0.947
4	1e+12	NDD	37.509	38.656	1.1467
5	5e+12	NDD	32.353	35.144	2.791
6	5e+12	NDD	37.987	38.66	0.6733
7	5e+12	NDD	33.767	34.835	1.0686
8	5e+12	NDD	35.559	38.476	2.9174
9	1e+13	NDD	36.469	37.328	0.8587
10	1e+13	NDD	36.523	37.419	0.8961
11	1e+13	NDD	34.973	37.666	2.693
12	1e+13	NDD	37.079	37.734	0.6555
13	0	CORRELATION	34.381	35.71	1.3287
14	0	CORRELATION	34.379	37.253	2.8737
15	0	CORRELATION	37.802	38.777	0.9745

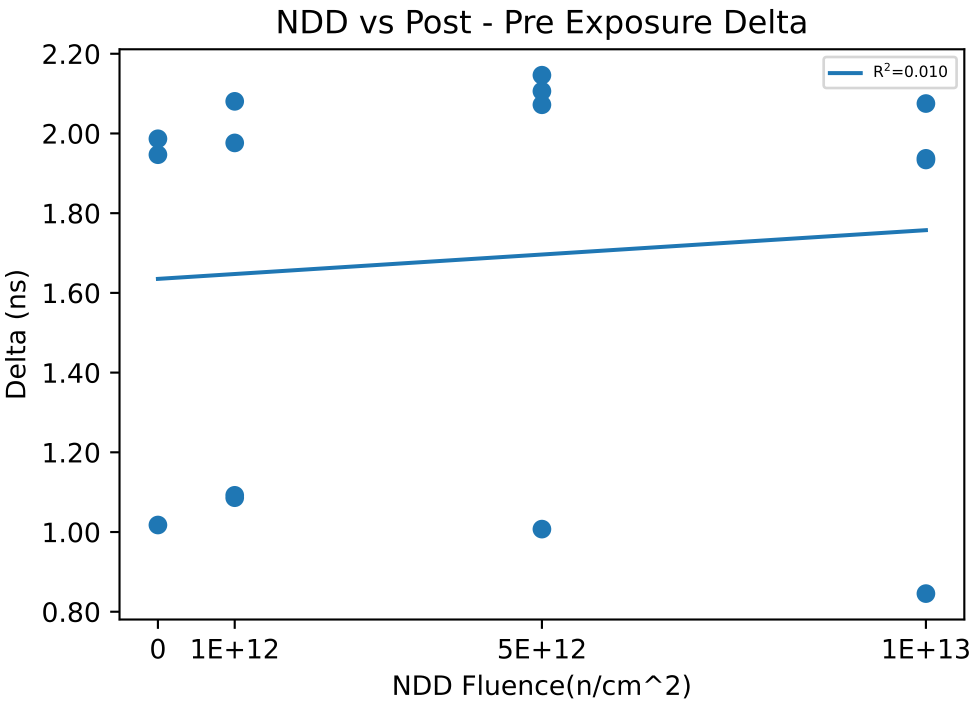


Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	34.379	35.521	37.802	1.9758	35.71	37.247	38.777	1.5336	0.9745	1.7256	2.8737	1.0099
1e+12	34.445	36.751	37.859	1.5614	37.275	38.285	39.073	0.77466	0.947	1.5344	2.8304	0.87139
5e+12	32.353	34.916	37.987	2.431	34.835	36.779	38.66	2.0711	0.6733	1.8626	2.9174	1.1575
1e+13	34.973	36.261	37.079	0.90171	37.328	37.537	37.734	0.19438	0.6555	1.2758	2.693	0.95068

Device Test: 26.1 TIMING|MIN/OUT/4.5/4.5/0/0/4.5/500kHz//@TON_MIN





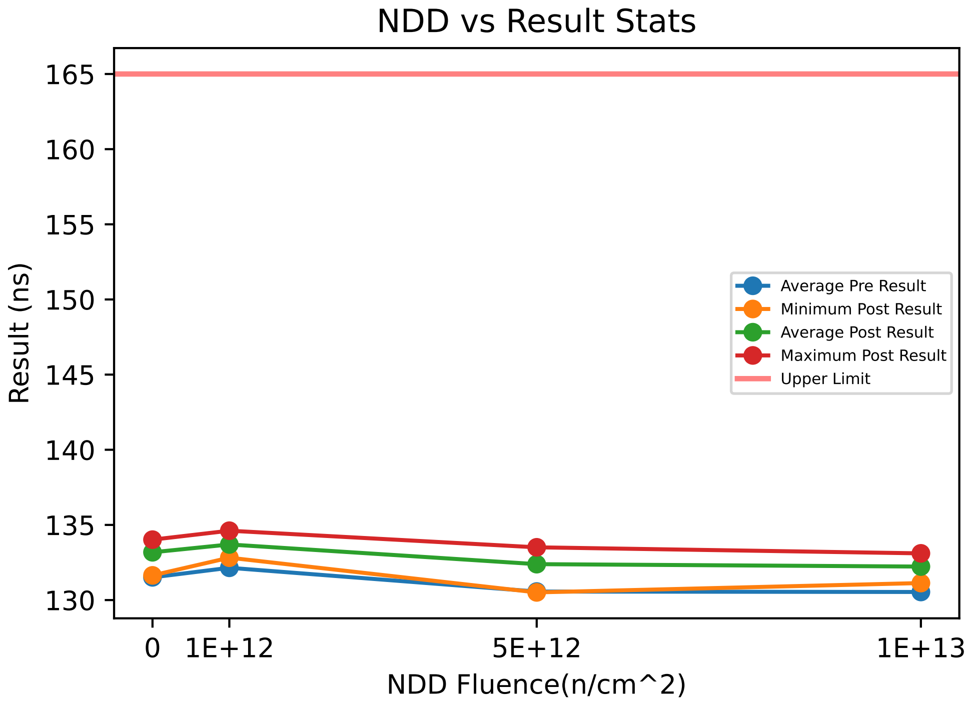
Test Results (Upper Limit = 165.0 (ns))

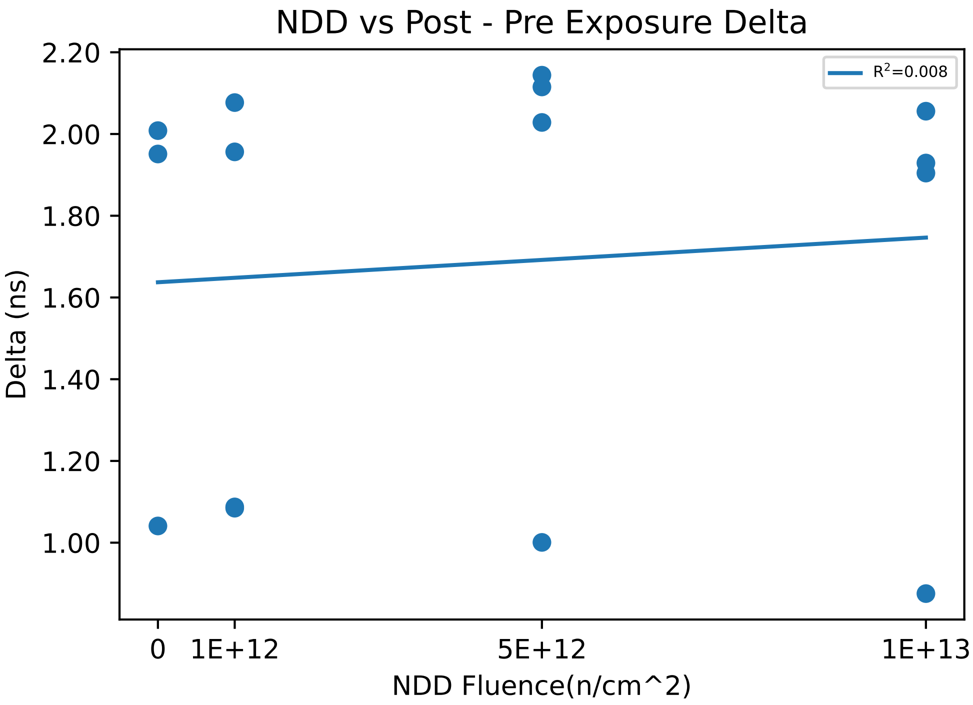
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	137.09	138.18	1.0921
2	1e+12	NDD	137.3	139.38	2.0806
3	1e+12	NDD	135.58	137.56	1.9763
4	1e+12	NDD	137.42	138.51	1.0861
5	5e+12	NDD	133.15	135.3	2.1462
6	5e+12	NDD	134.84	136.91	2.072
7	5e+12	NDD	136.96	137.96	1.0073
8	5e+12	NDD	136.02	138.13	2.1061
9	1e+13	NDD	134.65	136.59	1.9335
10	1e+13	NDD	136.42	137.26	0.8455
11	1e+13	NDD	135.77	137.85	2.0751
12	1e+13	NDD	133.83	135.77	1.9376
13	0	CORRELATION	135.23	136.25	1.0176
14	0	CORRELATION	136.82	138.8	1.9867
15	0	CORRELATION	136.6	138.55	1.9467

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.23	136.22	136.82	0.86163	136.25	137.87	138.8	1.4086	1.0176	1.6503	1.9867	0.54833
1e+12	135.58	136.85	137.42	0.85492	137.56	138.41	139.38	0.7577	1.0861	1.5588	2.0806	0.54401
5e+12	133.15	135.24	136.96	1.6403	135.3	137.07	138.13	1.3009	1.0073	1.8329	2.1462	0.55123
1e+13	133.83	135.17	136.42	1.1501	135.77	136.87	137.85	0.89357	0.8455	1.6979	2.0751	0.57208

Device Test: 26.2 TIMING|MIN/OUT/5/5/0/0/5/500kHz//@TON_MIN


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

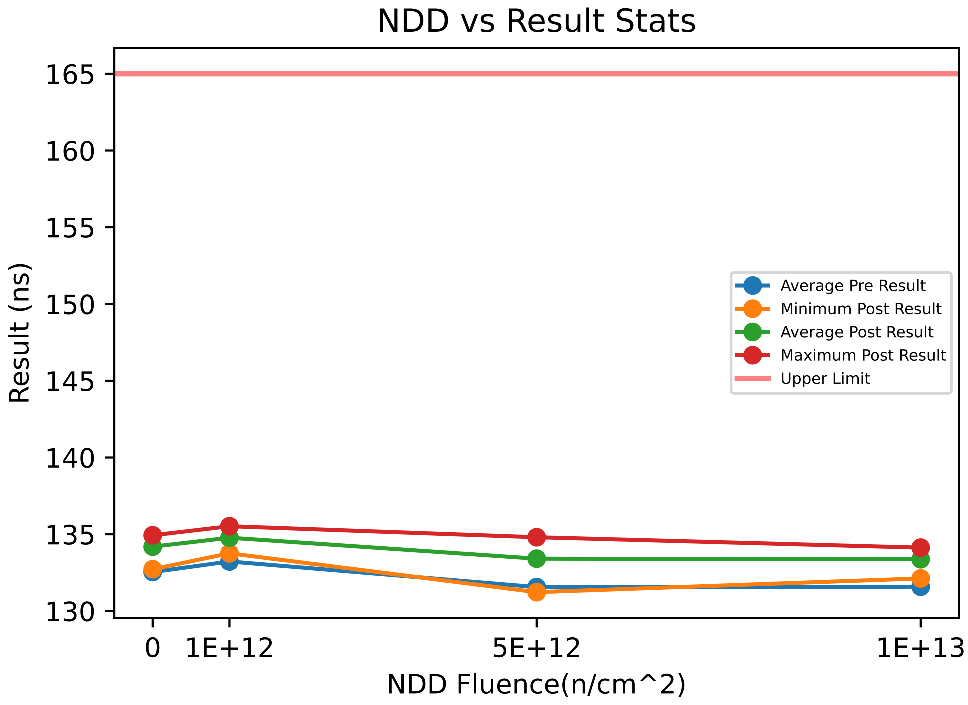
Test Results (Upper Limit = 165.0 (ns))

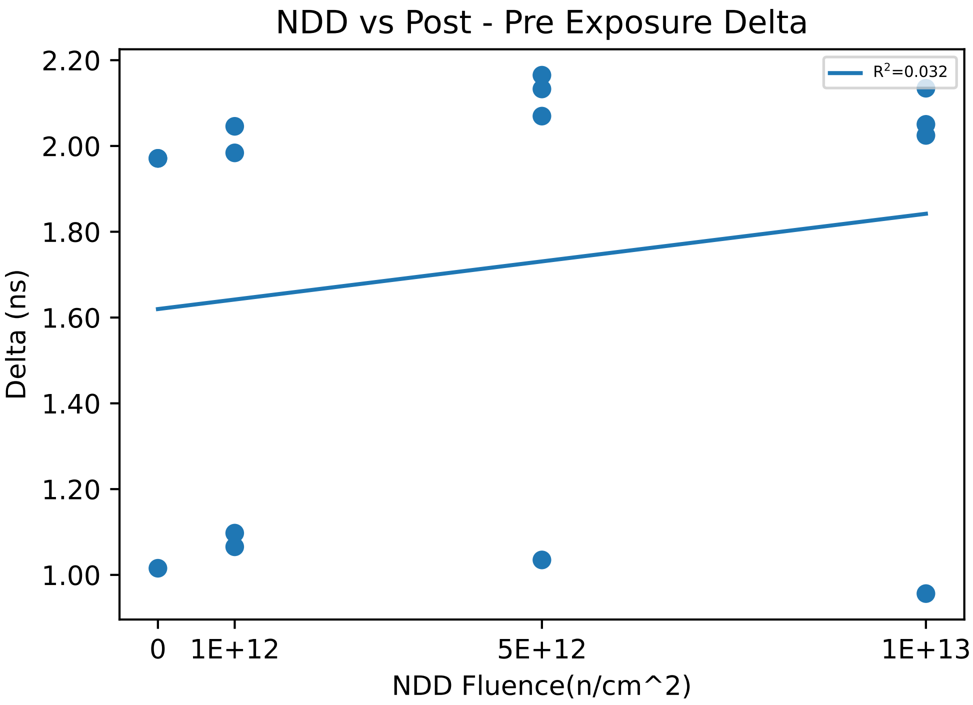
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	132.4	133.49	1.0844
2	1e+12	NDD	132.54	134.61	2.0769
3	1e+12	NDD	130.86	132.82	1.9563
4	1e+12	NDD	132.78	133.87	1.0875
5	5e+12	NDD	128.37	130.51	2.1439
6	5e+12	NDD	130.34	132.37	2.0283
7	5e+12	NDD	132.17	133.17	1.0007
8	5e+12	NDD	131.39	133.51	2.1152
9	1e+13	NDD	130.12	132.02	1.9044
10	1e+13	NDD	131.78	132.65	0.8754
11	1e+13	NDD	131.05	133.11	2.0558
12	1e+13	NDD	129.2	131.13	1.929
13	0	CORRELATION	130.6	131.64	1.0409
14	0	CORRELATION	132.01	134.02	2.0083
15	0	CORRELATION	131.92	133.88	1.9511

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.6	131.51	132.01	0.78996	131.64	133.18	134.02	1.3327	1.0409	1.6668	2.0083	0.54277
1e+12	130.86	132.15	132.78	0.87081	132.82	133.7	134.61	0.74988	1.0844	1.5513	2.0769	0.53956
5e+12	128.37	130.57	132.17	1.6484	130.51	132.39	133.51	1.3415	1.0007	1.822	2.1439	0.54975
1e+13	129.2	130.54	131.78	1.1199	131.13	132.23	133.11	0.85608	0.8754	1.6911	2.0558	0.54786

Device Test: 26.3 TIMING|MIN/OUT/12/12/0/0/5/500kHz//@TON_MIN





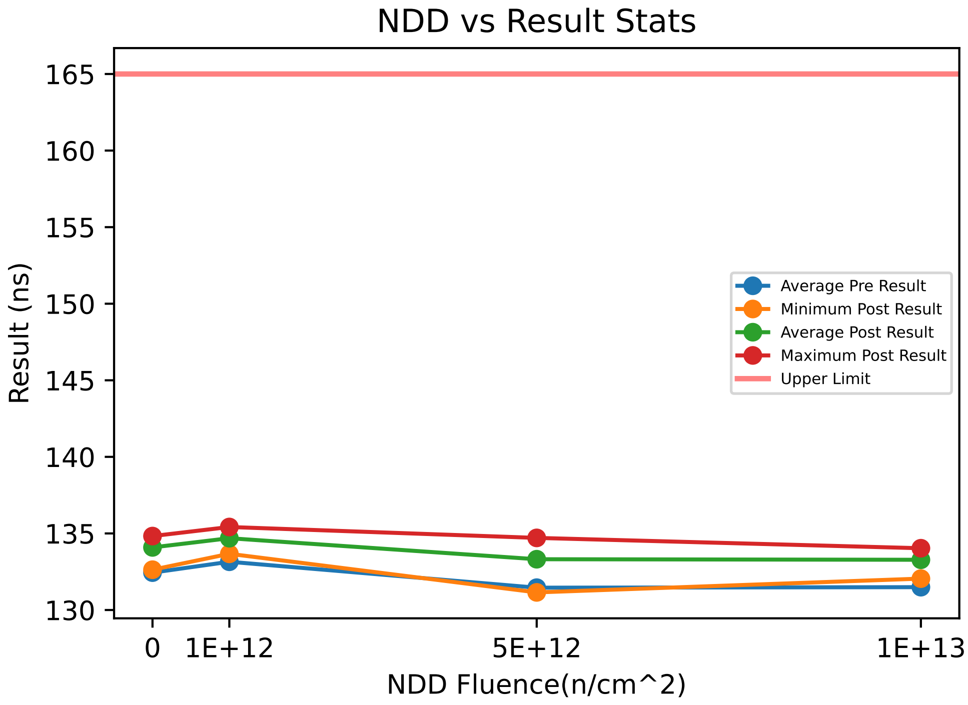
Test Results (Upper Limit = 165.0 (ns))

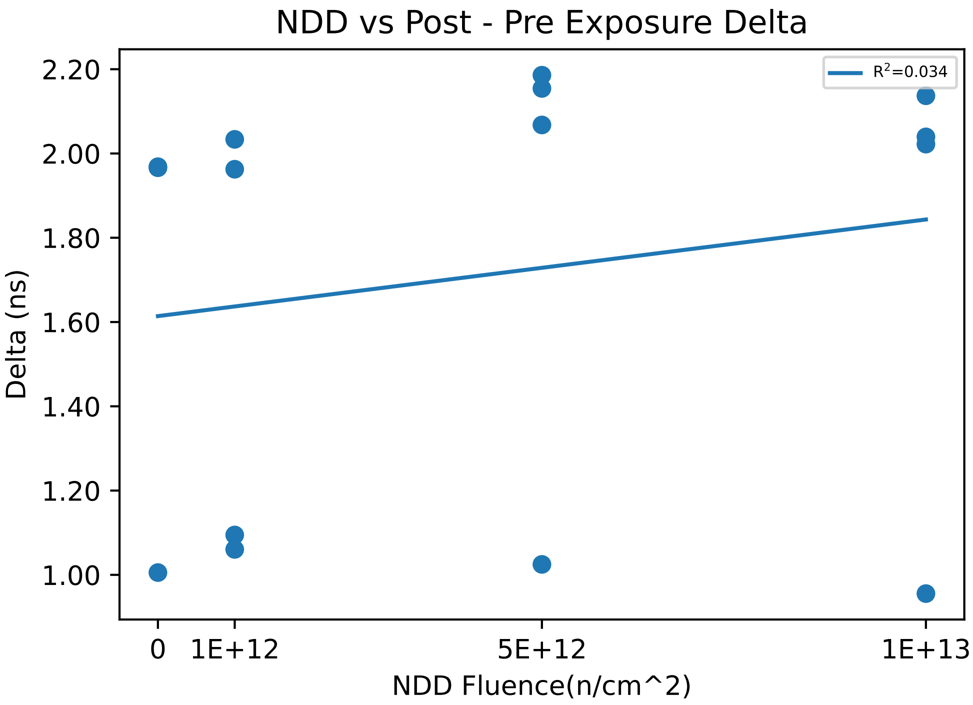
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	133.66	134.76	1.0974
2	1e+12	NDD	133.48	135.52	2.0458
3	1e+12	NDD	131.78	133.76	1.9839
4	1e+12	NDD	133.99	135.06	1.0655
5	5e+12	NDD	129.06	131.23	2.165
6	5e+12	NDD	131.39	133.46	2.0696
7	5e+12	NDD	133.12	134.15	1.0349
8	5e+12	NDD	132.67	134.81	2.1329
9	1e+13	NDD	131.22	133.24	2.0246
10	1e+13	NDD	133.04	134	0.9564
11	1e+13	NDD	132	134.13	2.1346
12	1e+13	NDD	130.07	132.12	2.0504
13	0	CORRELATION	131.71	132.73	1.0155
14	0	CORRELATION	132.96	134.93	1.971
15	0	CORRELATION	132.95	134.92	1.9712

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	131.71	132.54	132.96	0.71939	132.73	134.19	134.93	1.2711	1.0155	1.6526	1.9712	0.55172
1e+12	131.78	133.23	133.99	0.99082	133.76	134.78	135.52	0.7466	1.0655	1.5482	2.0458	0.53965
5e+12	129.06	131.56	133.12	1.8184	131.23	133.41	134.81	1.5554	1.0349	1.8506	2.165	0.54524
1e+13	130.07	131.58	133.04	1.2534	132.12	133.37	134.13	0.92058	0.9564	1.7915	2.1346	0.55871

Device Test: 26.4 TIMING|MIN/OUT/14/14/0/0/5/500kHz//@TON_MIN





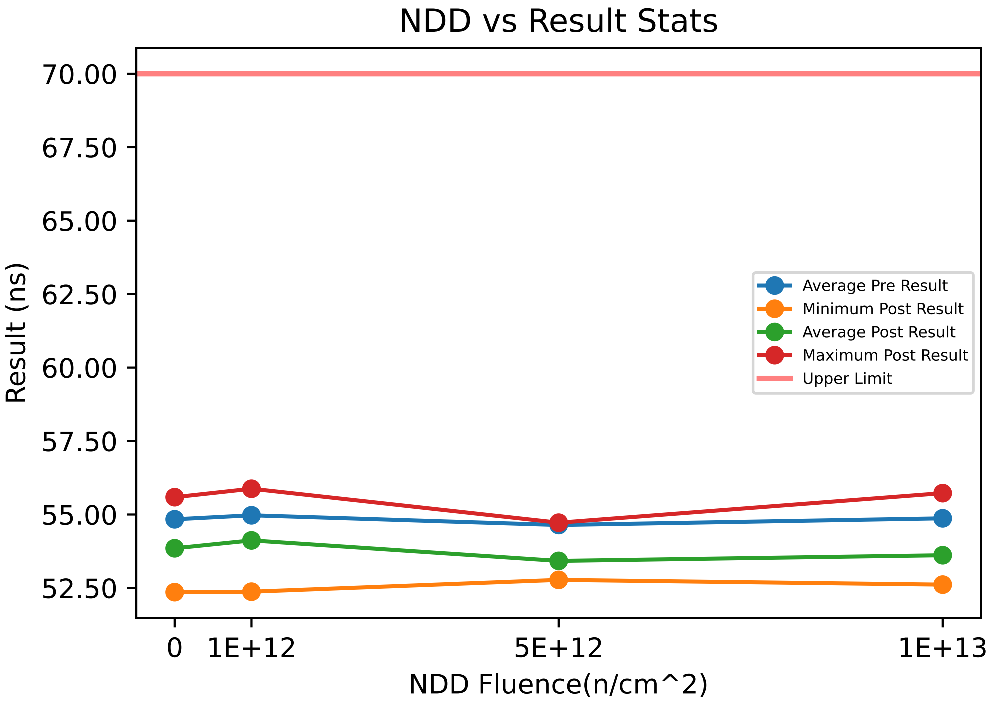
Test Results (Upper Limit = 165.0 (ns))

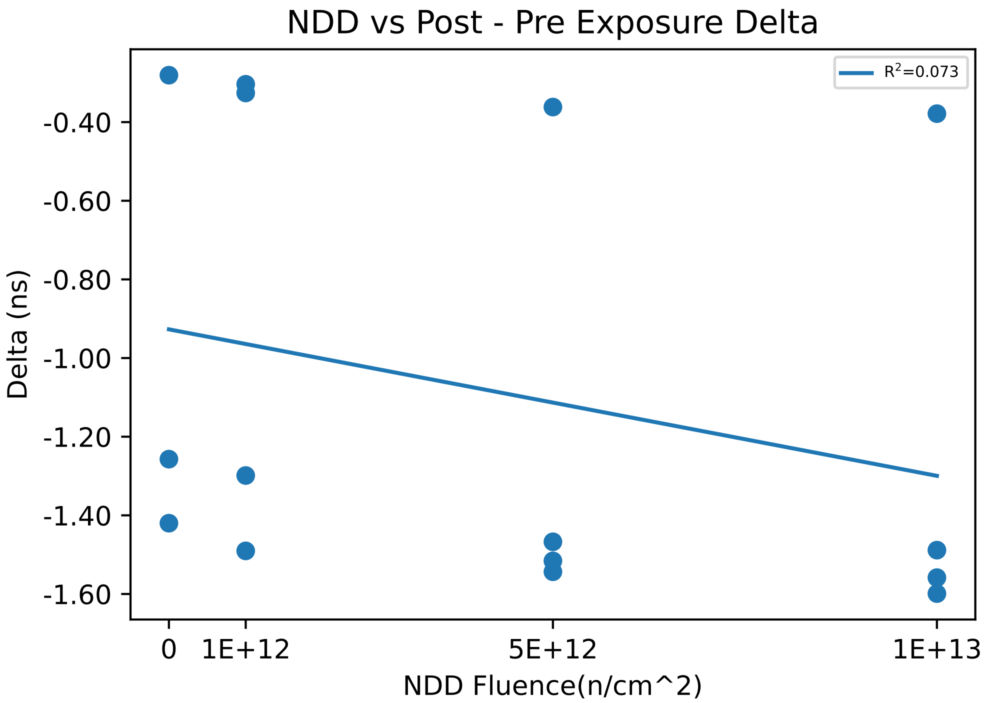
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	133.61	134.7	1.0946
2	1e+12	NDD	133.39	135.42	2.0335
3	1e+12	NDD	131.71	133.67	1.9626
4	1e+12	NDD	133.9	134.96	1.0604
5	5e+12	NDD	128.96	131.15	2.1858
6	5e+12	NDD	131.29	133.36	2.0677
7	5e+12	NDD	133.02	134.04	1.0248
8	5e+12	NDD	132.55	134.71	2.1544
9	1e+13	NDD	131.12	133.14	2.0222
10	1e+13	NDD	132.94	133.9	0.9555
11	1e+13	NDD	131.9	134.03	2.137
12	1e+13	NDD	130.01	132.05	2.0394
13	0	CORRELATION	131.63	132.63	1.0054
14	0	CORRELATION	132.86	134.83	1.9662
15	0	CORRELATION	132.84	134.8	1.9686

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	131.63	132.44	132.86	0.70604	132.63	134.09	134.83	1.2614	1.0054	1.6467	1.9686	0.55541
1e+12	131.71	133.15	133.9	0.98512	133.67	134.69	135.42	0.74137	1.0604	1.5378	2.0335	0.53245
5e+12	128.96	131.46	133.02	1.8155	131.15	133.32	134.71	1.5454	1.0248	1.8582	2.1858	0.55782
1e+13	130.01	131.49	132.94	1.238	132.05	133.28	134.03	0.90928	0.9555	1.7885	2.137	0.55765

Device Test: 26.5 TIMING|EXT/OUT/4.5/4.5/0/0/4.5/500kHz//@T_OFF_EXTENDER





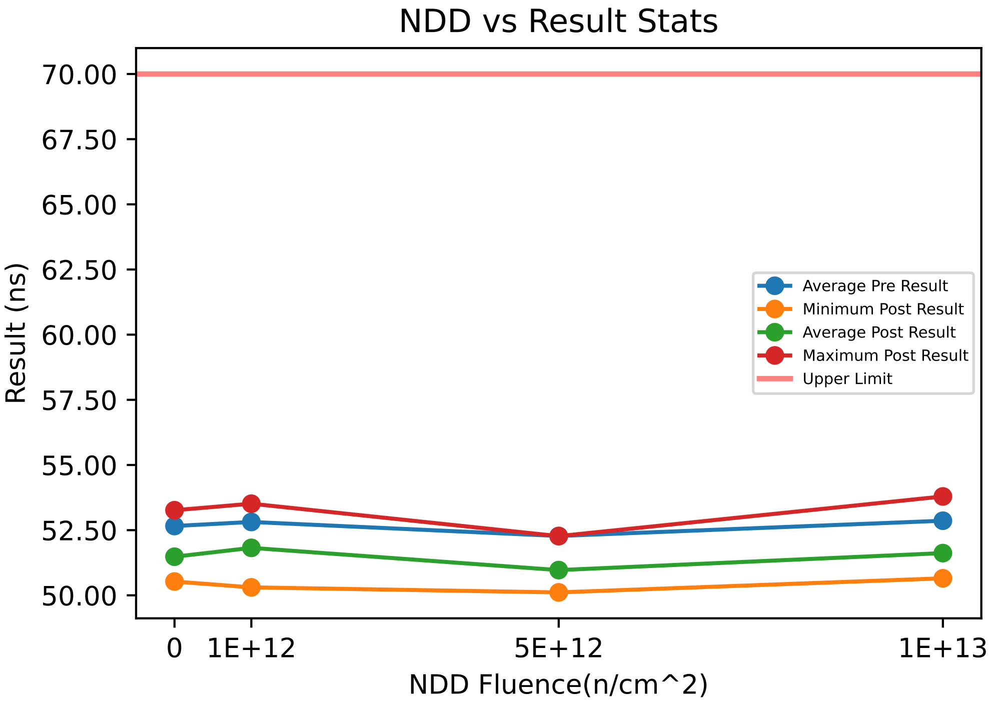
Test Results (Upper Limit = 70.0 (ns))

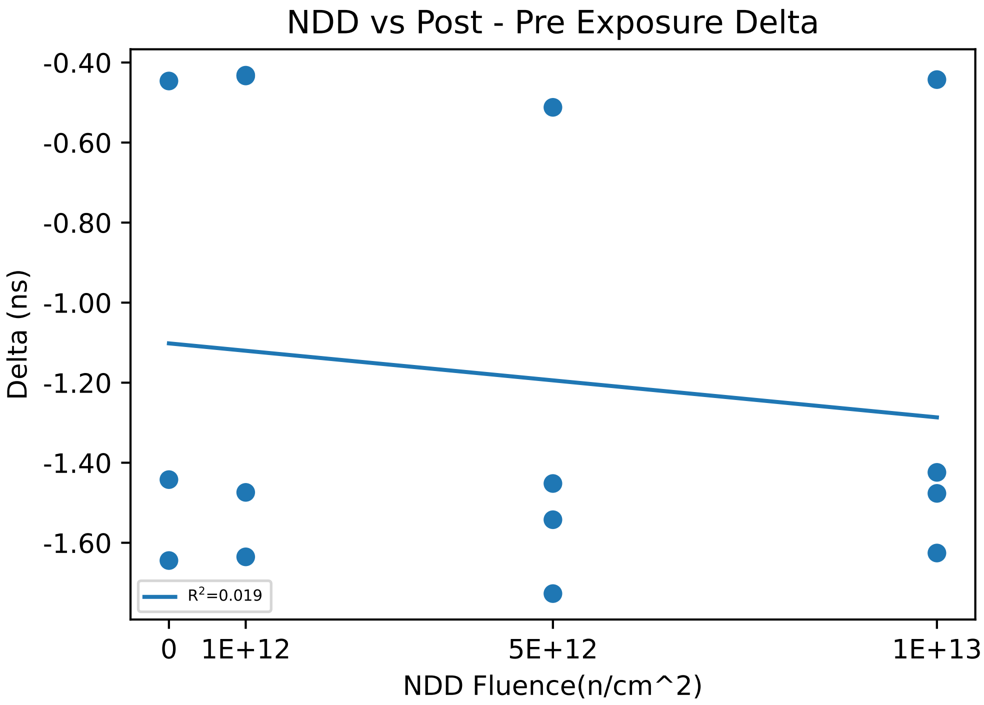
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	56.18	55.877	-0.3038
2	1e+12	NDD	54.697	53.206	-1.4904
3	1e+12	NDD	53.672	52.373	-1.2987
4	1e+12	NDD	55.344	55.018	-0.3259
5	5e+12	NDD	54.614	53.098	-1.5158
6	5e+12	NDD	54.242	52.775	-1.4673
7	5e+12	NDD	55.083	54.721	-0.3617
8	5e+12	NDD	54.633	53.089	-1.5435
9	1e+13	NDD	54.213	52.614	-1.599
10	1e+13	NDD	56.105	55.727	-0.3785
11	1e+13	NDD	54.931	53.372	-1.5584
12	1e+13	NDD	54.231	52.743	-1.4885
13	0	CORRELATION	55.87	55.59	-0.2807
14	0	CORRELATION	55.026	53.606	-1.42
15	0	CORRELATION	53.614	52.357	-1.2571

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.614	54.837	55.87	1.1398	52.357	53.851	55.59	1.63	-1.42	-0.98593	-0.2807	0.61616
1e+12	53.672	54.973	56.18	1.0592	52.373	54.118	55.877	1.6103	-1.4904	-0.8547	-0.3038	0.62832
5e+12	54.242	54.643	55.083	0.34405	52.775	53.421	54.721	0.87985	-1.5435	-1.2221	-0.3617	0.57445
1e+13	54.213	54.87	56.105	0.88884	52.614	53.614	55.727	1.4471	-1.599	-1.2561	-0.3785	0.58684

Device Test: 26.7 TIMING|EXT/OUT/14/14/0/0/5/500kHz//@T_OFF_EXTENDER





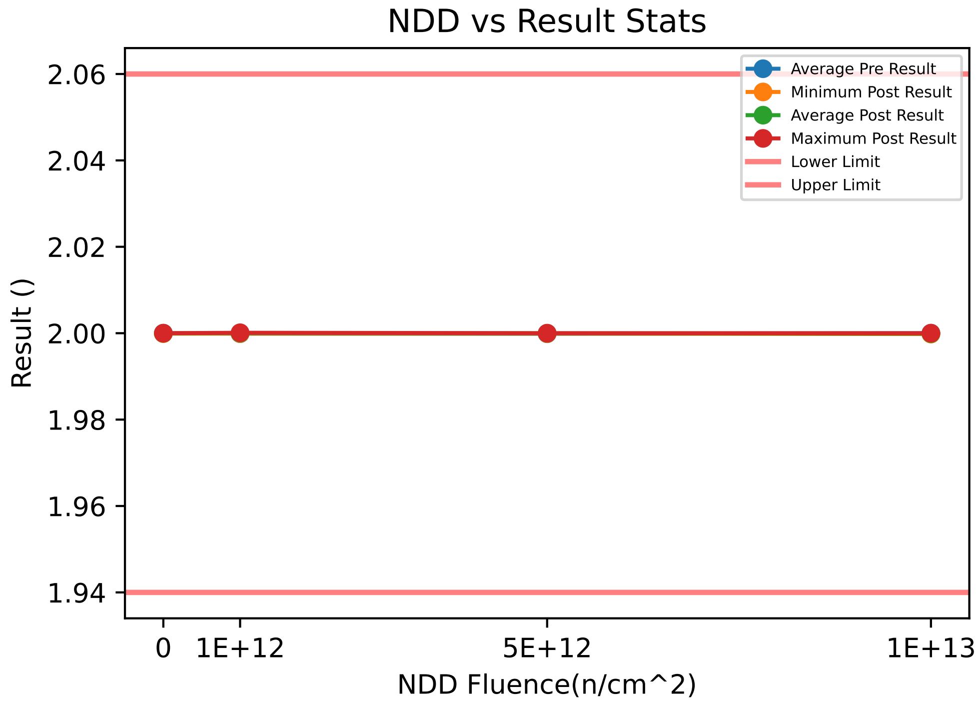
Test Results (Upper Limit = 70.0 (ns))

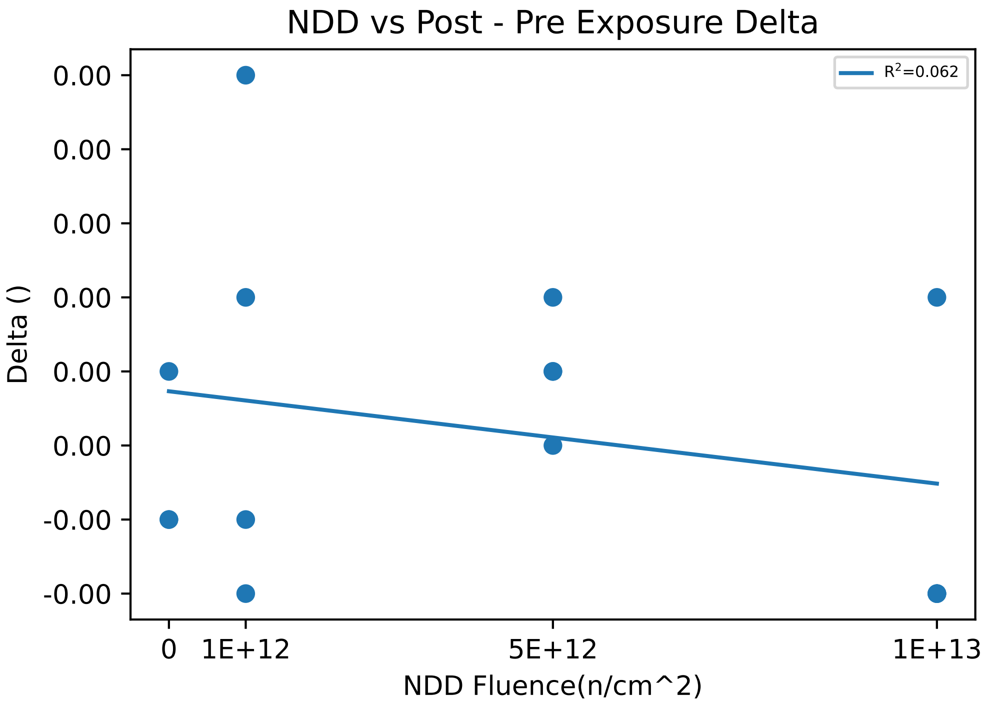
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	53.947	53.515	-0.4317
2	1e+12	NDD	51.941	50.305	-1.6352
3	1e+12	NDD	52.008	50.534	-1.4741
4	1e+12	NDD	53.362	52.929	-0.4336
5	5e+12	NDD	51.839	50.112	-1.727
6	5e+12	NDD	52.165	50.713	-1.4519
7	5e+12	NDD	52.783	52.271	-0.512
8	5e+12	NDD	52.317	50.775	-1.5424
9	1e+13	NDD	52.46	51.036	-1.4241
10	1e+13	NDD	54.236	53.793	-0.4427
11	1e+13	NDD	52.622	50.996	-1.6256
12	1e+13	NDD	52.129	50.653	-1.4766
13	0	CORRELATION	53.711	53.264	-0.4462
14	0	CORRELATION	52.294	50.649	-1.6444
15	0	CORRELATION	51.972	50.53	-1.4422

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.972	52.659	53.711	0.92491	50.53	51.481	53.264	1.5454	-1.6444	-1.1776	-0.4462	0.64143
1e+12	51.941	52.815	53.947	0.99928	50.305	51.821	53.515	1.638	-1.6352	-0.99365	-0.4317	0.65112
5e+12	51.839	52.276	52.783	0.39256	50.112	50.968	52.271	0.91896	-1.727	-1.3083	-0.512	0.54309
1e+13	52.129	52.862	54.236	0.93882	50.653	51.62	53.793	1.4594	-1.6256	-1.2422	-0.4427	0.53982

Device Test: 28.1 LEVEL|RATIO/CS/4.5/4.5/0/0/4.5/500kHz//@C_CS_R





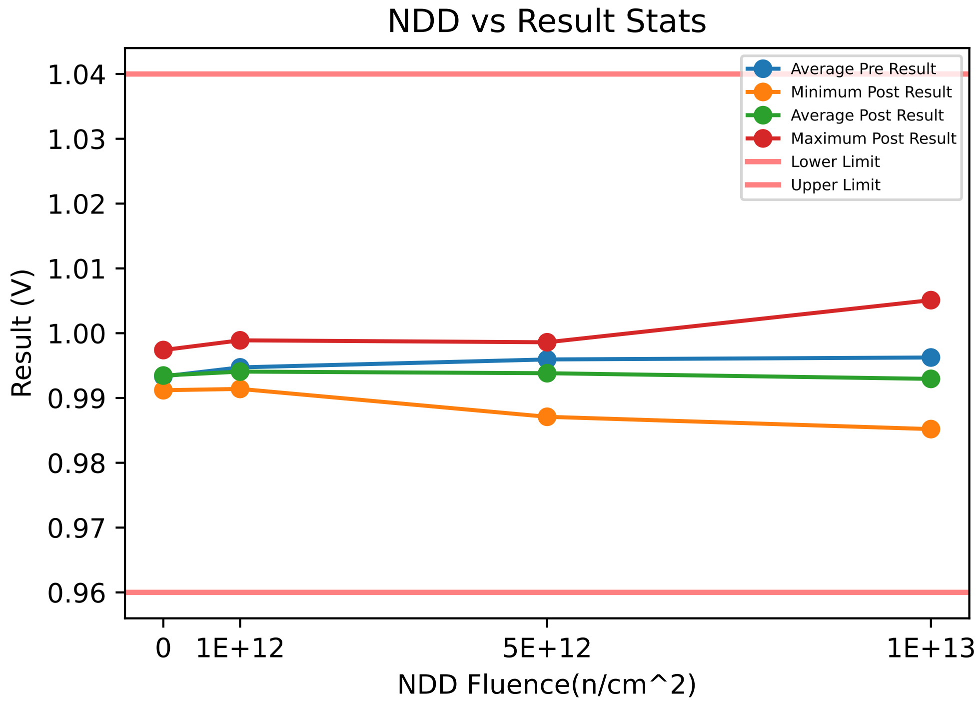
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

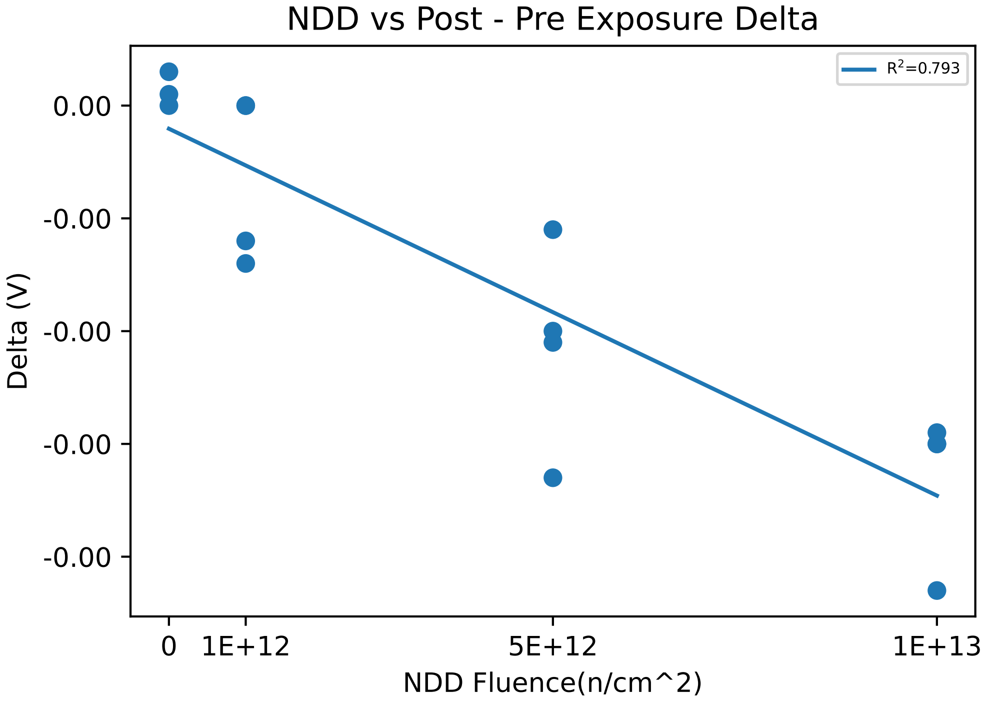
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.9998	2	0.0002
2	1e+12	NDD	2.0001	1.9999	-0.0002
3	1e+12	NDD	1.9996	2.0001	0.0005
4	1e+12	NDD	2.0001	2	-0.0001
5	5e+12	NDD	2	2	0
6	5e+12	NDD	1.9998	1.9999	0.0001
7	5e+12	NDD	1.9998	2	0.0002
8	5e+12	NDD	1.9999	2	0.0001
9	1e+13	NDD	2.0001	1.9999	-0.0002
10	1e+13	NDD	1.9998	2	0.0002
11	1e+13	NDD	2	1.9998	-0.0002
12	1e+13	NDD	2.0001	1.9999	-0.0002
13	0	CORRELATION	1.9999	2	0.0001
14	0	CORRELATION	2	1.9999	-0.0001
15	0	CORRELATION	2.0001	2	-0.0001

Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2.0001	0.0001	1.9999	2	2	5.7735e-05	-0.0001	-3.3333e-05	0.0001	0.00011547
1e+12	1.9996	1.9999	2.0001	0.00024495	1.9999	2	2.0001	8.165e-05	-0.0002	0.0001	0.0005	0.00031623
5e+12	1.9998	1.9999	2	9.5743e-05	1.9999	2	2	5e-05	0	0.0001	0.0002	8.165e-05
1e+13	1.9998	2	2.0001	0.00014142	1.9998	1.9999	2	8.165e-05	-0.0002	-0.0001	0.0002	0.0002

Device Test: 28.10 VOLTAGE|OC/CS/5/5/0/0/5/100kHz//@V_CS_ILIM_OC


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

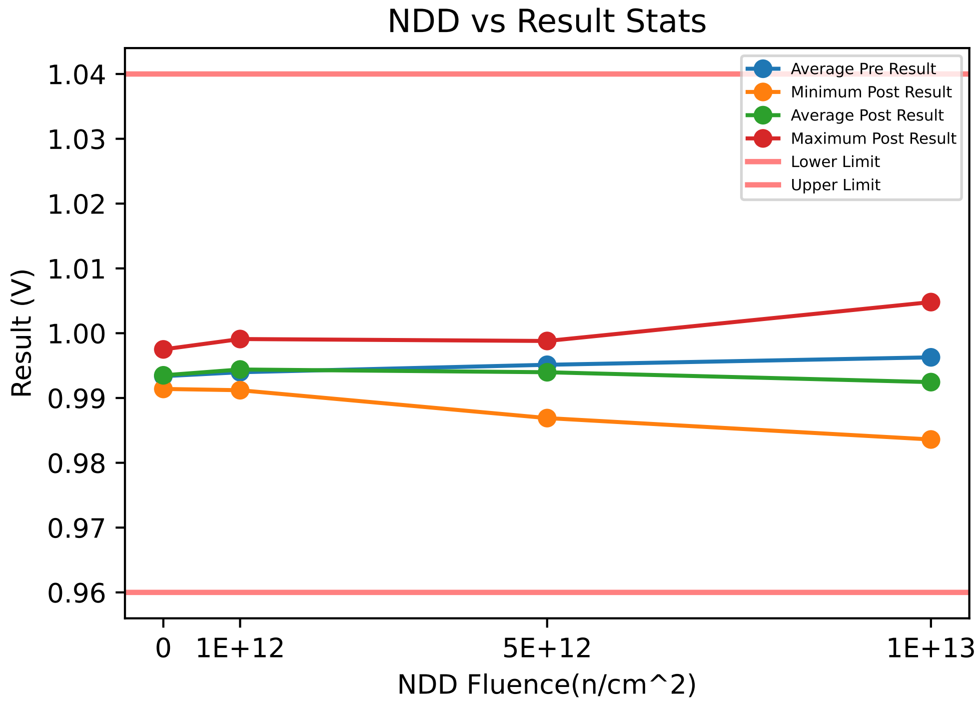
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

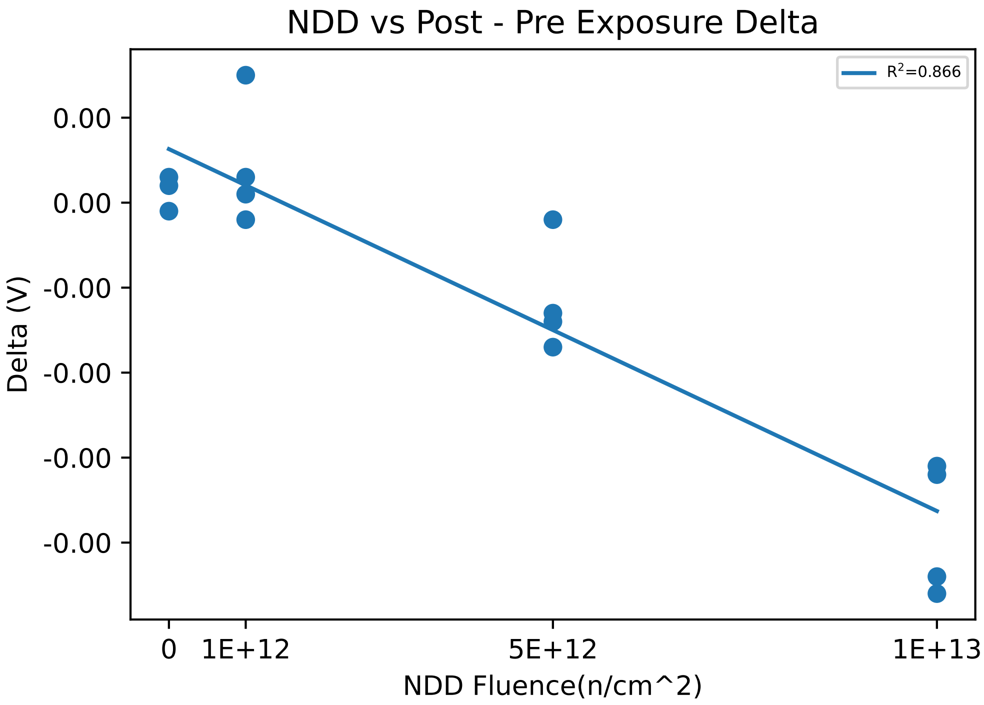
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9989	0.9989	0
2	1e+12	NDD	0.9943	0.9929	-0.0014
3	1e+12	NDD	0.9914	0.9914	0
4	1e+12	NDD	0.9943	0.9931	-0.0012
5	5e+12	NDD	1.0004	0.9971	-0.0033
6	5e+12	NDD	1.0007	0.9986	-0.0021
7	5e+12	NDD	0.9882	0.9871	-0.0011
8	5e+12	NDD	0.9945	0.9925	-0.002
9	1e+13	NDD	0.9929	0.9886	-0.0043
10	1e+13	NDD	1.008	1.0051	-0.0029
11	1e+13	NDD	0.9959	0.9929	-0.003
12	1e+13	NDD	0.9882	0.9852	-0.003
13	0	CORRELATION	0.9915	0.9918	0.0003
14	0	CORRELATION	0.9973	0.9974	0.0001
15	0	CORRELATION	0.9912	0.9912	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.99333	0.9973	0.0034385	0.9912	0.99347	0.9974	0.0034196	0	0.00013333	0.0003	0.00015275
1e+12	0.9914	0.99472	0.9989	0.0031009	0.9914	0.99408	0.9989	0.0033049	-0.0014	-0.00065	0	0.00075498
5e+12	0.9882	0.99595	1.0007	0.0059028	0.9871	0.99382	0.9986	0.0051803	-0.0033	-0.002125	-0.0011	0.00090323
1e+13	0.9882	0.99625	1.008	0.00845	0.9852	0.99295	1.0051	0.0086912	-0.0043	-0.0033	-0.0029	0.00066833

Device Test: 28.11 VOLTAGE|OC/CS/12/12/0/0/5/100kHz//@V_CS_ILIM_OC


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

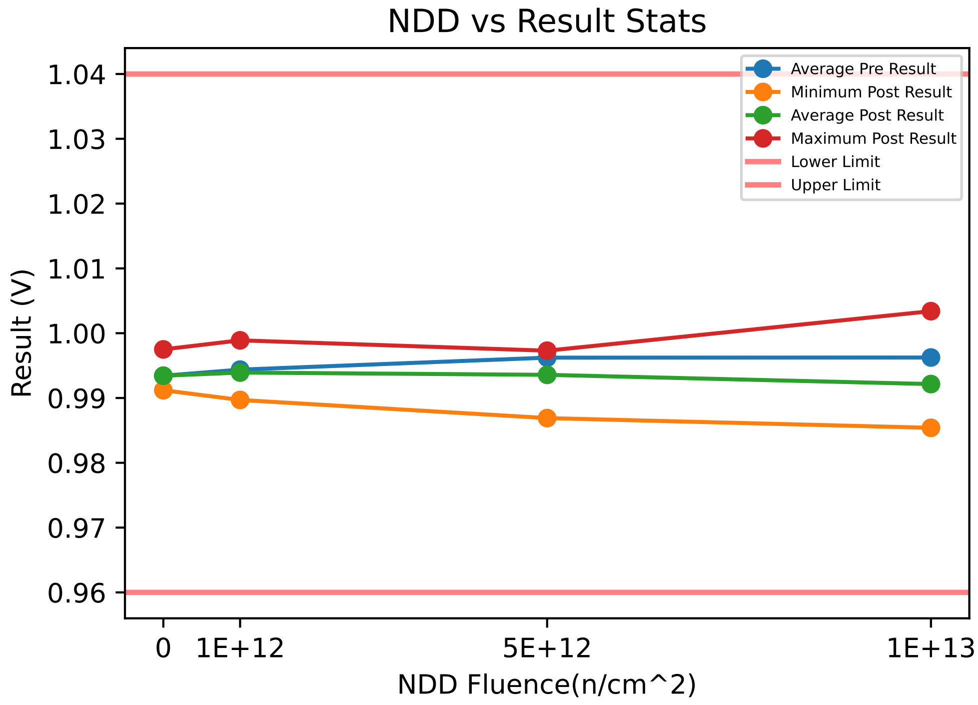
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

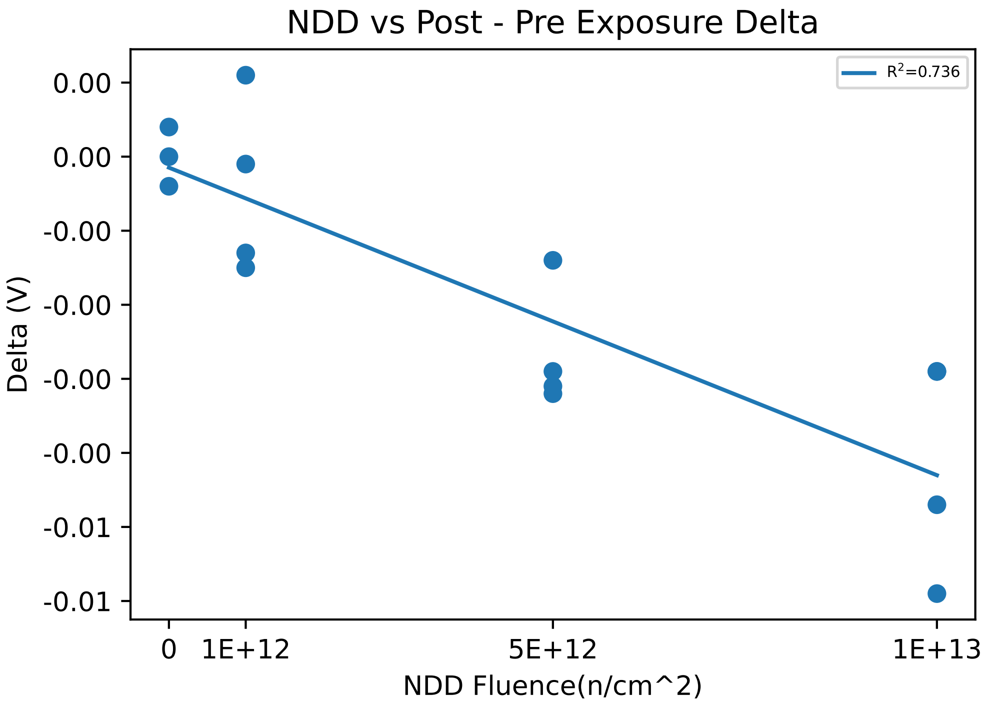
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9988	0.9991	0.0003
2	1e+12	NDD	0.9929	0.9944	0.0015
3	1e+12	NDD	0.9914	0.9912	-0.0002
4	1e+12	NDD	0.9928	0.9929	0.0001
5	5e+12	NDD	0.9989	0.9976	-0.0013
6	5e+12	NDD	0.999	0.9988	-0.0002
7	5e+12	NDD	0.9883	0.9869	-0.0014
8	5e+12	NDD	0.9943	0.9926	-0.0017
9	1e+13	NDD	0.993	0.9886	-0.0044
10	1e+13	NDD	1.008	1.0048	-0.0032
11	1e+13	NDD	0.9959	0.9928	-0.0031
12	1e+13	NDD	0.9882	0.9836	-0.0046
13	0	CORRELATION	0.9915	0.9914	-0.0001
14	0	CORRELATION	0.9973	0.9975	0.0002
15	0	CORRELATION	0.9913	0.9916	0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9913	0.99337	0.9973	0.0034078	0.9914	0.9935	0.9975	0.0034655	-0.0001	0.00013333	0.0003	0.00020817
1e+12	0.9914	0.99398	0.9988	0.0032887	0.9912	0.9944	0.9991	0.0033951	-0.0002	0.000425	0.0015	0.00074554
5e+12	0.9883	0.99513	0.999	0.0050507	0.9869	0.99398	0.9988	0.0054273	-0.0017	-0.00115	-0.0002	0.00065574
1e+13	0.9882	0.99628	1.008	0.008437	0.9836	0.99245	1.0048	0.0090515	-0.0046	-0.003825	-0.0031	0.00078475

Device Test: 28.12 VOLTAGE|OC/CS/14/14/0/0/5/100kHz//@V_CS_ILIM_OC


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

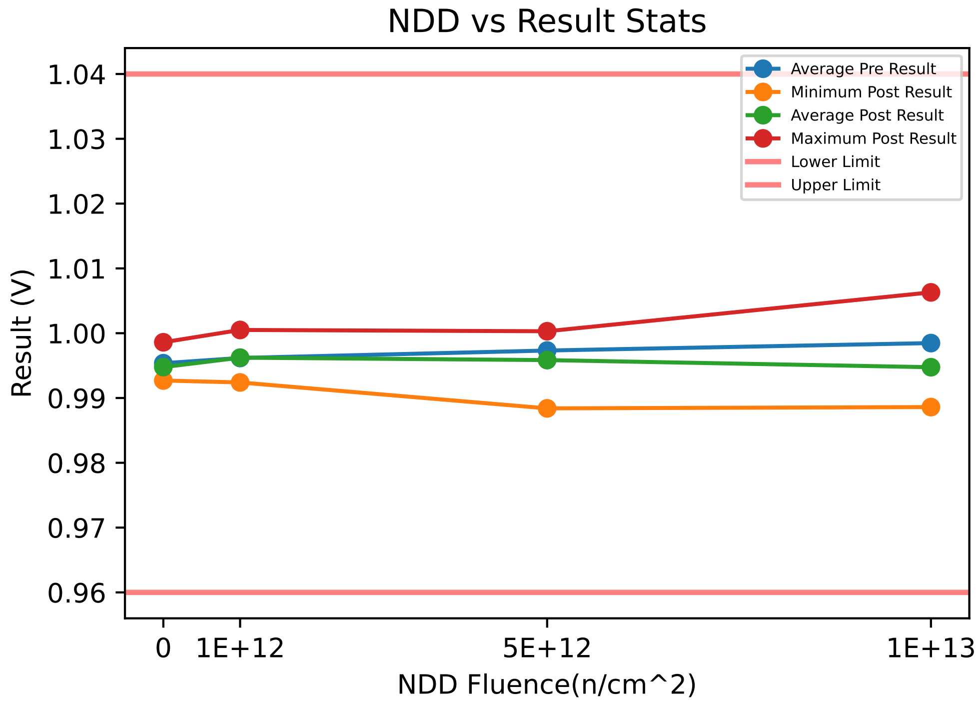
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.999	0.9989	-0.0001
2	1e+12	NDD	0.993	0.9941	0.0011
3	1e+12	NDD	0.9912	0.9897	-0.0015
4	1e+12	NDD	0.9943	0.993	-0.0013
5	5e+12	NDD	1.0004	0.9973	-0.0031
6	5e+12	NDD	1.0004	0.9972	-0.0032
7	5e+12	NDD	0.9883	0.9869	-0.0014
8	5e+12	NDD	0.9958	0.9929	-0.0029
9	1e+13	NDD	0.9928	0.9869	-0.0059
10	1e+13	NDD	1.0081	1.0034	-0.0047
11	1e+13	NDD	0.9958	0.9929	-0.0029
12	1e+13	NDD	0.9883	0.9854	-0.0029
13	0	CORRELATION	0.9912	0.9916	0.0004
14	0	CORRELATION	0.9975	0.9975	0
15	0	CORRELATION	0.9916	0.9912	-0.0004

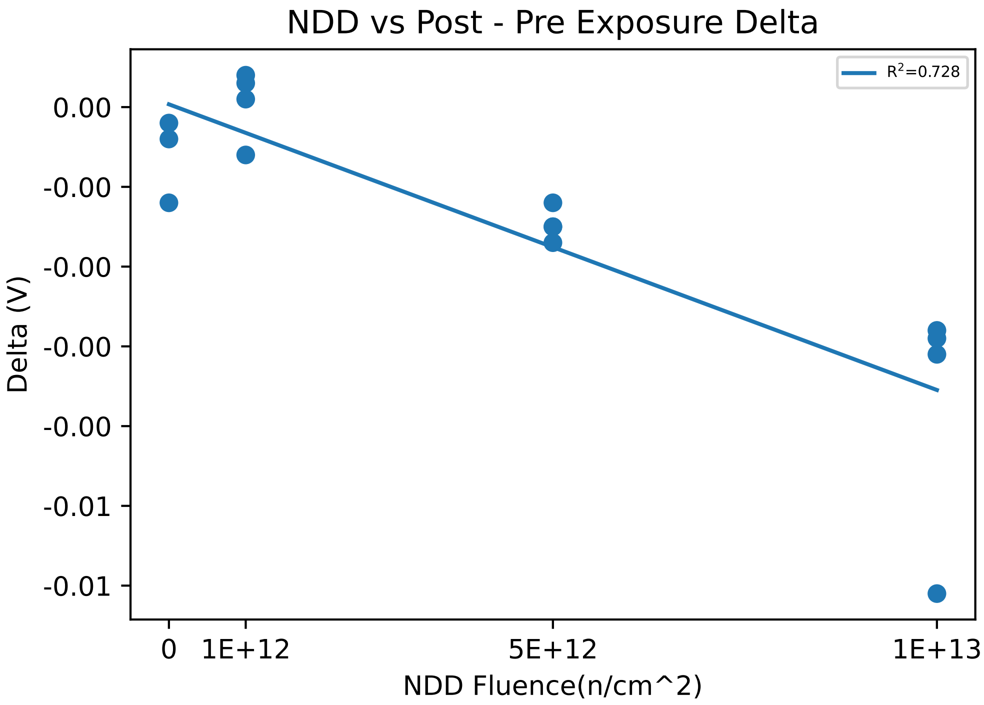
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.99343	0.9975	0.0035275	0.9912	0.99343	0.9975	0.0035275	-0.0004	0	0.0004	0.0004
1e+12	0.9912	0.99438	0.999	0.003335	0.9897	0.99392	0.9989	0.0038073	-0.0015	-0.00045	0.0011	0.0012042
5e+12	0.9883	0.99622	1.0004	0.005711	0.9869	0.99357	0.9973	0.0048999	-0.0032	-0.00265	-0.0014	0.00084261
1e+13	0.9883	0.99625	1.0081	0.00848	0.9854	0.99215	1.0034	0.0081701	-0.0059	-0.0041	-0.0029	0.0014697

Device Test: 28.13 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/500kHz//@V_CS_ILIM_OC



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

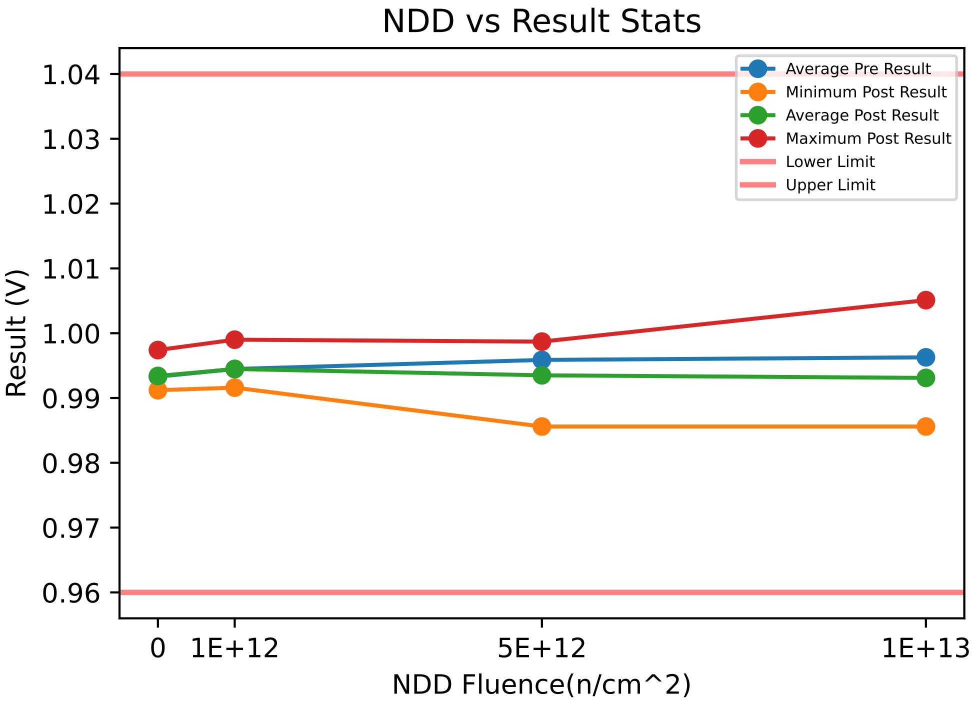
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

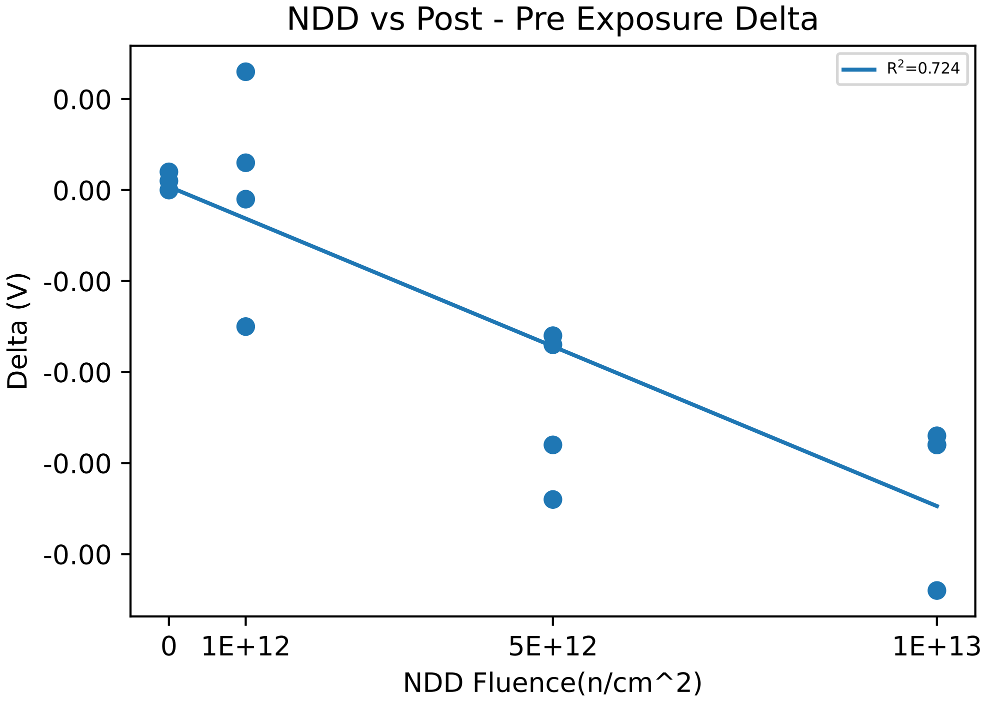
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.0001	1.0005	0.0004
2	1e+12	NDD	0.9959	0.996	0.0001
3	1e+12	NDD	0.993	0.9924	-0.0006
4	1e+12	NDD	0.9957	0.996	0.0003
5	5e+12	NDD	1.0018	1.0003	-0.0015
6	5e+12	NDD	1.0018	1.0001	-0.0017
7	5e+12	NDD	0.9899	0.9884	-0.0015
8	5e+12	NDD	0.9958	0.9946	-0.0012
9	1e+13	NDD	0.9958	0.9897	-0.0061
10	1e+13	NDD	1.0094	1.0063	-0.0031
11	1e+13	NDD	0.9973	0.9944	-0.0029
12	1e+13	NDD	0.9914	0.9886	-0.0028
13	0	CORRELATION	0.9942	0.993	-0.0012
14	0	CORRELATION	0.999	0.9986	-0.0004
15	0	CORRELATION	0.9929	0.9927	-0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9929	0.99537	0.999	0.003213	0.9927	0.99477	0.9986	0.0033232	-0.0012	-0.0006	-0.0002	0.00052915
1e+12	0.993	0.99618	1.0001	0.0029319	0.9924	0.99622	1.0005	0.003317	-0.0006	5e-05	0.0004	0.00045092
5e+12	0.9899	0.99733	1.0018	0.0057011	0.9884	0.99585	1.0003	0.0056252	-0.0017	-0.001475	-0.0012	0.00020616
1e+13	0.9914	0.99848	1.0094	0.0077017	0.9886	0.99475	1.0063	0.0081004	-0.0061	-0.003725	-0.0028	0.0015882

Device Test: 28.14 VOLTAGE|OC/CS/5/5/0/0/5/500kHz//@V_CS_ILIM_OC





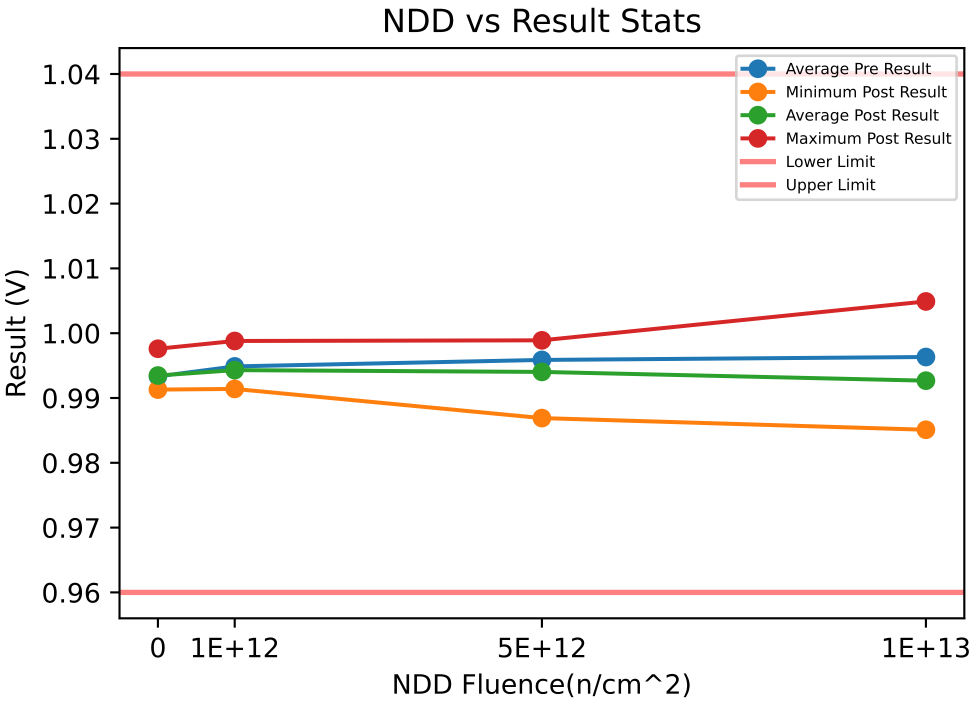
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

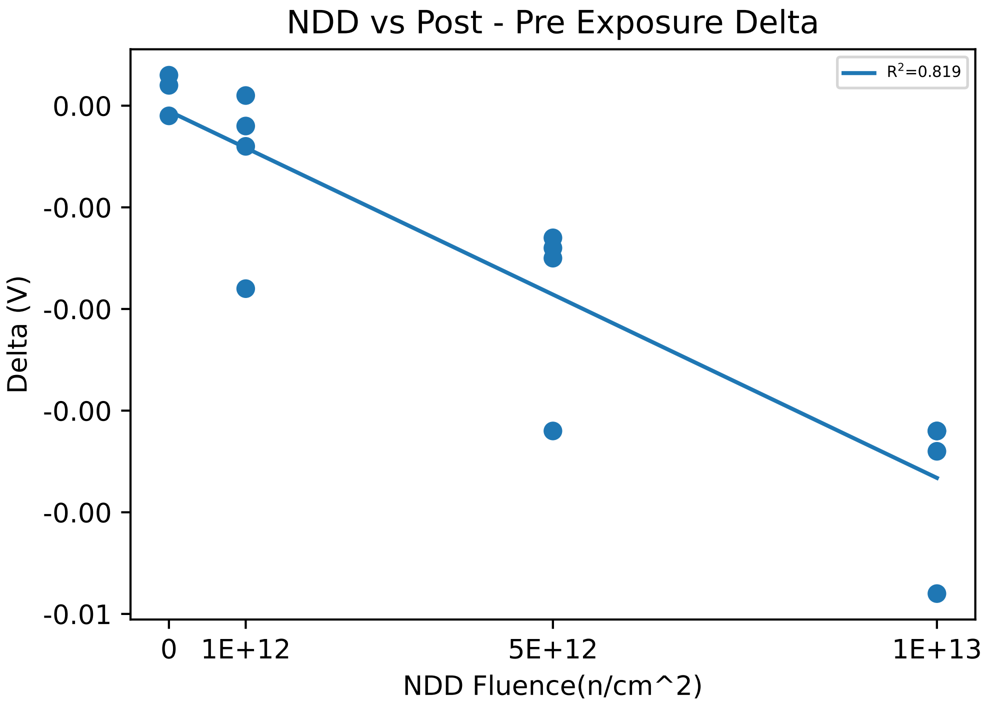
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9991	0.999	-0.0001
2	1e+12	NDD	0.993	0.9943	0.0013
3	1e+12	NDD	0.9913	0.9916	0.0003
4	1e+12	NDD	0.9945	0.993	-0.0015
5	5e+12	NDD	1.0005	0.9971	-0.0034
6	5e+12	NDD	1.0003	0.9987	-0.0016
7	5e+12	NDD	0.9884	0.9856	-0.0028
8	5e+12	NDD	0.9943	0.9926	-0.0017
9	1e+13	NDD	0.993	0.9886	-0.0044
10	1e+13	NDD	1.0079	1.0051	-0.0028
11	1e+13	NDD	0.9958	0.9931	-0.0027
12	1e+13	NDD	0.9884	0.9856	-0.0028
13	0	CORRELATION	0.9914	0.9916	0.0002
14	0	CORRELATION	0.9973	0.9974	0.0001
15	0	CORRELATION	0.9912	0.9912	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.9933	0.9973	0.0034655	0.9912	0.9934	0.9974	0.0034699	0	0.0001	0.0002	0.0001
1e+12	0.9913	0.99447	0.9991	0.003349	0.9916	0.99447	0.999	0.0032118	-0.0015	0	0.0013	0.0011605
5e+12	0.9884	0.99587	1.0005	0.0057541	0.9856	0.9935	0.9987	0.0058657	-0.0034	-0.002375	-0.0016	0.00087321
1e+13	0.9884	0.99628	1.0079	0.0083288	0.9856	0.9931	1.0051	0.0085732	-0.0044	-0.003175	-0.0027	0.00081803

Device Test: 28.15 VOLTAGE|OC/CS/12/12/0/0/5/500kHz//@V_CS_ILIM_OC


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

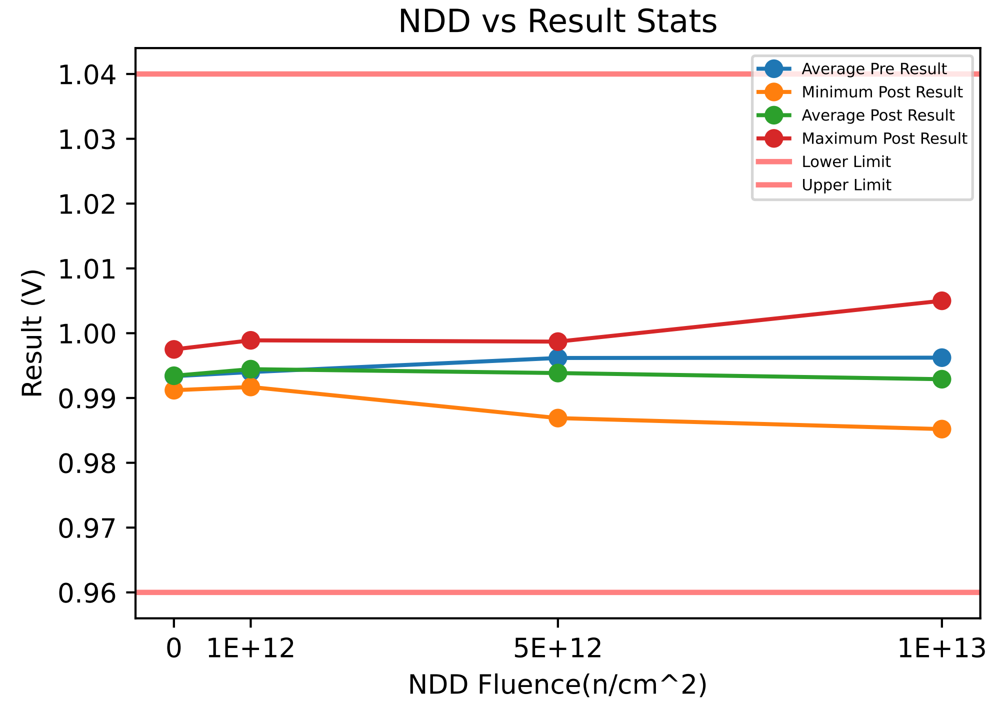
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

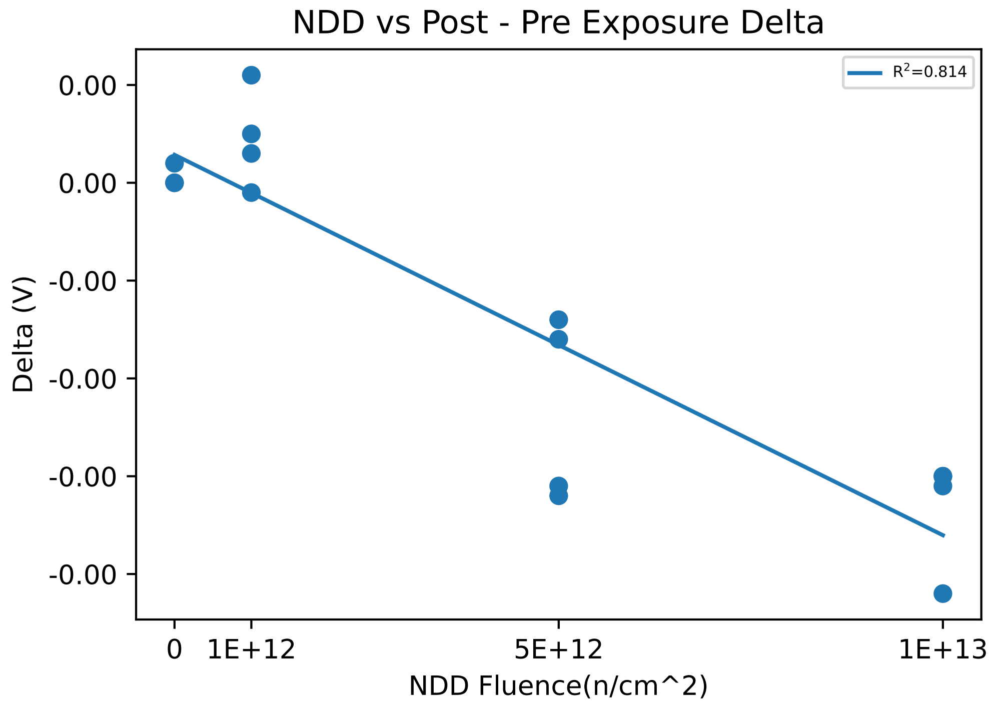
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.999	0.9988	-0.0002
2	1e+12	NDD	0.9945	0.9941	-0.0004
3	1e+12	NDD	0.9913	0.9914	0.0001
4	1e+12	NDD	0.9947	0.9929	-0.0018
5	5e+12	NDD	1.0005	0.9973	-0.0032
6	5e+12	NDD	1.0002	0.9989	-0.0013
7	5e+12	NDD	0.9883	0.9869	-0.0014
8	5e+12	NDD	0.9945	0.993	-0.0015
9	1e+13	NDD	0.9929	0.9881	-0.0048
10	1e+13	NDD	1.0083	1.0049	-0.0034
11	1e+13	NDD	0.9958	0.9926	-0.0032
12	1e+13	NDD	0.9883	0.9851	-0.0032
13	0	CORRELATION	0.9912	0.9915	0.0003
14	0	CORRELATION	0.9974	0.9976	0.0002
15	0	CORRELATION	0.9914	0.9913	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.99333	0.9974	0.0035233	0.9913	0.99347	0.9976	0.003581	-0.0001	0.00013333	0.0003	0.00020817
1e+12	0.9913	0.99487	0.999	0.0031606	0.9914	0.9943	0.9988	0.0031969	-0.0018	-0.000575	0.0001	0.00084212
5e+12	0.9883	0.99587	1.0005	0.0057552	0.9869	0.99402	0.9989	0.0053637	-0.0032	-0.00185	-0.0013	0.0009037
1e+13	0.9883	0.99633	1.0083	0.0085597	0.9851	0.99267	1.0049	0.0087134	-0.0048	-0.00365	-0.0032	0.00077244

Device Test: 28.16 VOLTAGE|OC/CS/14/14/0/0/5/500kHz//@V_CS_ILIM_OC





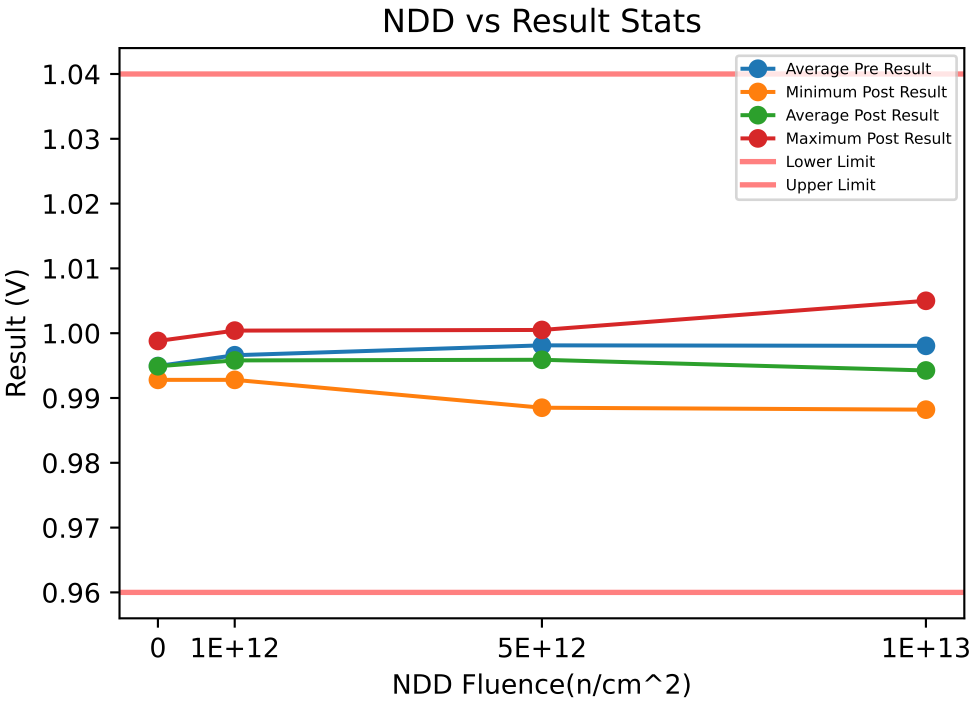
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

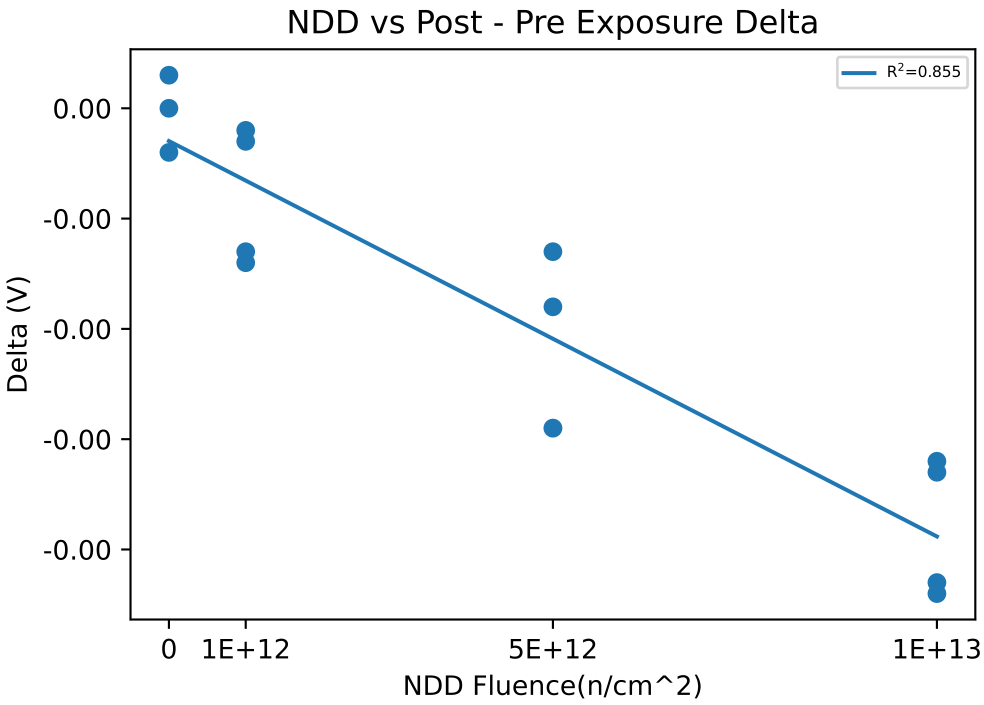
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.999	0.9989	-0.0001
2	1e+12	NDD	0.993	0.9941	0.0011
3	1e+12	NDD	0.9912	0.9917	0.0005
4	1e+12	NDD	0.9928	0.9931	0.0003
5	5e+12	NDD	1.0005	0.9973	-0.0032
6	5e+12	NDD	1.0003	0.9987	-0.0016
7	5e+12	NDD	0.9883	0.9869	-0.0014
8	5e+12	NDD	0.9956	0.9925	-0.0031
9	1e+13	NDD	0.9928	0.9886	-0.0042
10	1e+13	NDD	1.008	1.005	-0.003
11	1e+13	NDD	0.9958	0.9928	-0.003
12	1e+13	NDD	0.9883	0.9852	-0.0031
13	0	CORRELATION	0.9914	0.9916	0.0002
14	0	CORRELATION	0.9975	0.9975	0
15	0	CORRELATION	0.9912	0.9912	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.99337	0.9975	0.003581	0.9912	0.99343	0.9975	0.0035275	0	6.6667e-05	0.0002	0.00011547
1e+12	0.9912	0.994	0.999	0.0034293	0.9917	0.99445	0.9989	0.0031257	-0.0001	0.00045	0.0011	0.0005
5e+12	0.9883	0.99618	1.0005	0.0057174	0.9869	0.99385	0.9987	0.0053401	-0.0032	-0.002325	-0.0014	0.00095699
1e+13	0.9883	0.99622	1.008	0.0084334	0.9852	0.9929	1.005	0.0086448	-0.0042	-0.003325	-0.003	0.00058523

Device Test: 28.17 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/1MHz//@V_CS_ILIM_OC





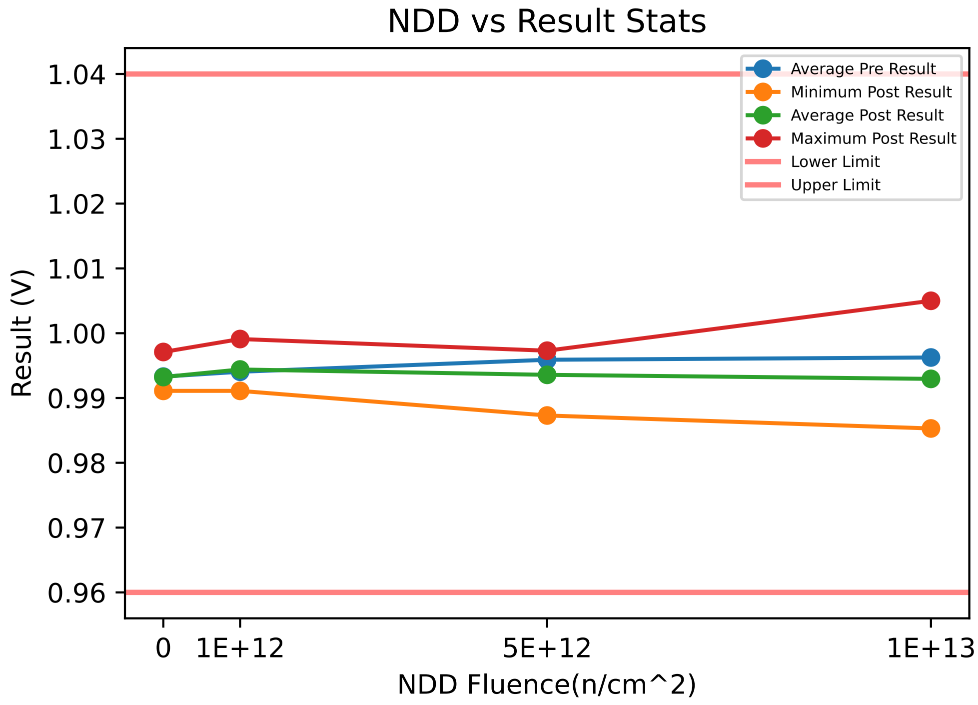
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

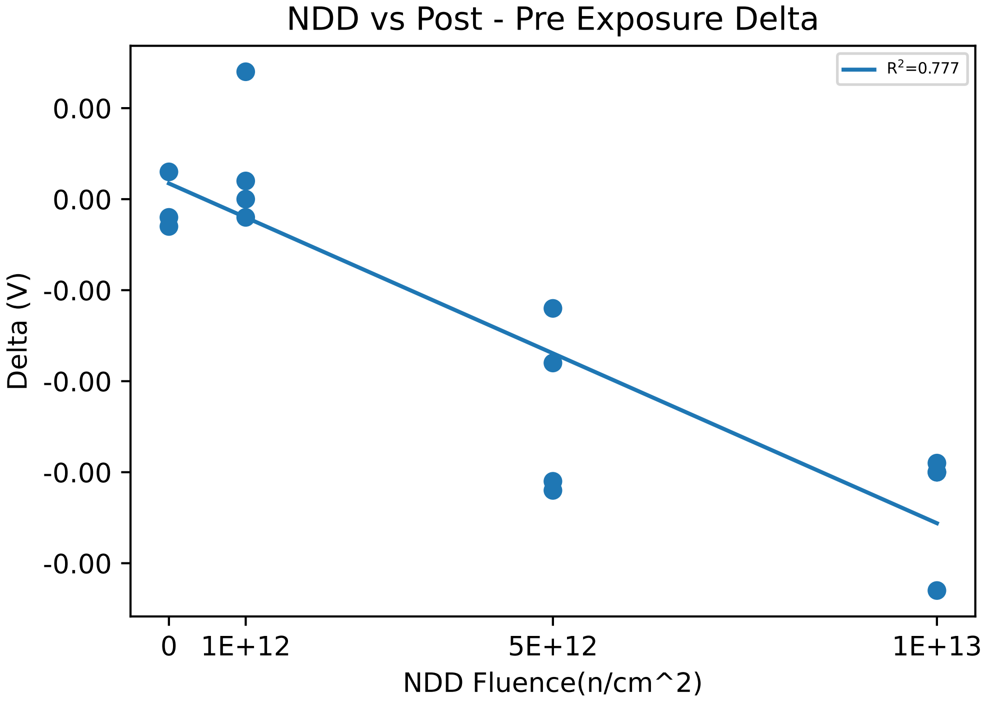
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.0018	1.0004	-0.0014
2	1e+12	NDD	0.9959	0.9956	-0.0003
3	1e+12	NDD	0.993	0.9928	-0.0002
4	1e+12	NDD	0.9957	0.9944	-0.0013
5	5e+12	NDD	1.0018	1.0005	-0.0013
6	5e+12	NDD	1.002	1.0002	-0.0018
7	5e+12	NDD	0.9914	0.9885	-0.0029
8	5e+12	NDD	0.9973	0.9944	-0.0029
9	1e+13	NDD	0.9942	0.9898	-0.0044
10	1e+13	NDD	1.0093	1.005	-0.0043
11	1e+13	NDD	0.9973	0.994	-0.0033
12	1e+13	NDD	0.9914	0.9882	-0.0032
13	0	CORRELATION	0.9932	0.9928	-0.0004
14	0	CORRELATION	0.9988	0.9988	0
15	0	CORRELATION	0.9928	0.9931	0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9928	0.99493	0.9988	0.0033546	0.9928	0.9949	0.9988	0.0033808	-0.0004	-3.3333e-05	0.0003	0.00035119
1e+12	0.993	0.9966	1.0018	0.0037103	0.9928	0.9958	1.0004	0.0032741	-0.0014	-0.0008	-0.0002	0.0006377
5e+12	0.9914	0.99812	1.002	0.0049809	0.9885	0.9959	1.0005	0.0056763	-0.0029	-0.002225	-0.0013	0.00080571
1e+13	0.9914	0.99805	1.0093	0.0078776	0.9882	0.99425	1.005	0.0075725	-0.0044	-0.0038	-0.0032	0.0006377

Device Test: 28.18 VOLTAGE|OC/CS/5/5/0/0/5/1MHz//@V_CS_ILIM_OC





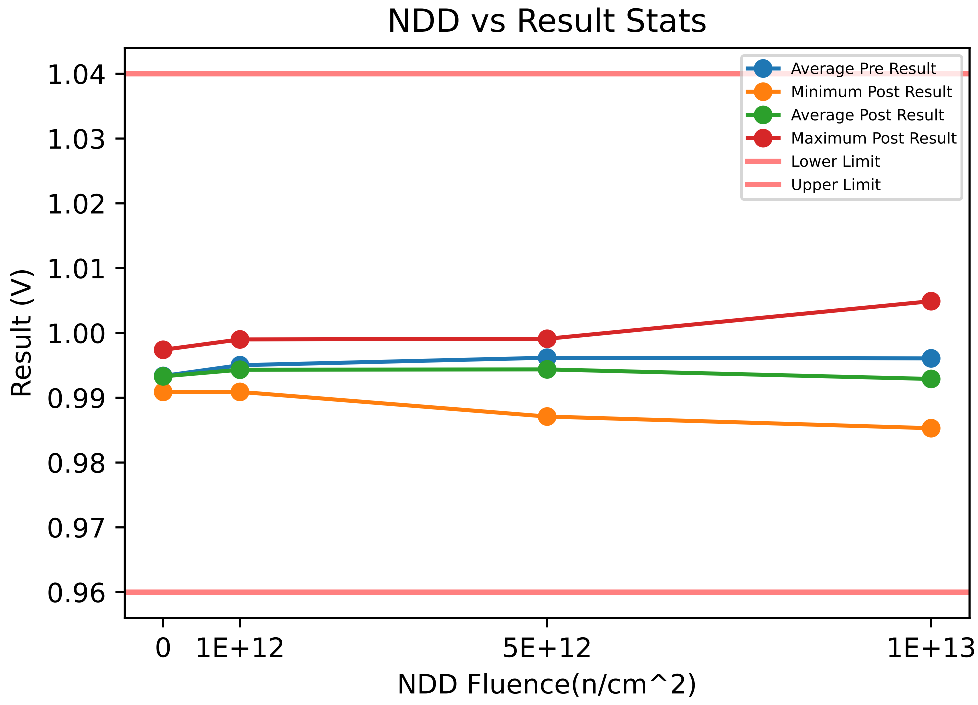
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

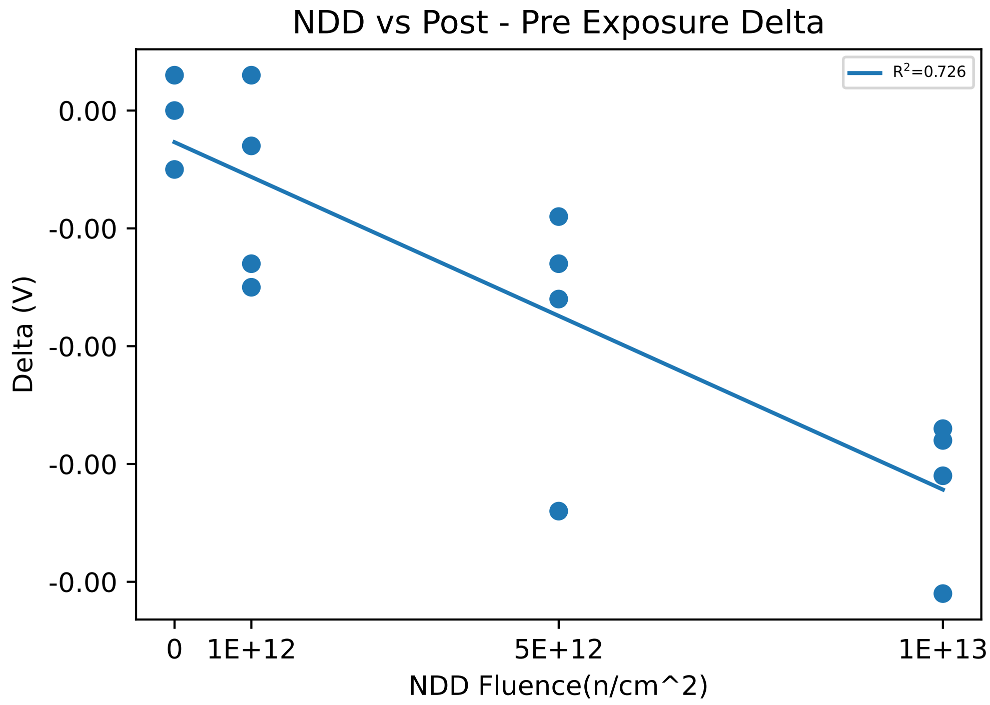
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	0.9989	0.9991	0.0002
2	1e+12	NDD	0.993	0.9944	0.0014
3	1e+12	NDD	0.9913	0.9911	-0.0002
4	1e+12	NDD	0.993	0.993	0
5	5e+12	NDD	1.0005	0.9973	-0.0032
6	5e+12	NDD	1.0003	0.9972	-0.0031
7	5e+12	NDD	0.9885	0.9873	-0.0012
8	5e+12	NDD	0.9943	0.9925	-0.0018
9	1e+13	NDD	0.9929	0.9886	-0.0043
10	1e+13	NDD	1.008	1.005	-0.003
11	1e+13	NDD	0.9958	0.9929	-0.0029
12	1e+13	NDD	0.9883	0.9853	-0.003
13	0	CORRELATION	0.9912	0.9915	0.0003
14	0	CORRELATION	0.9974	0.9971	-0.0003
15	0	CORRELATION	0.9913	0.9911	-0.0002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9912	0.9933	0.9974	0.0035511	0.9911	0.99323	0.9971	0.0033546	-0.0003	-6.6667e-05	0.0003	0.00032146
1e+12	0.9913	0.99405	0.9989	0.0033312	0.9911	0.9944	0.9991	0.0034127	-0.0002	0.00035	0.0014	0.0007188
5e+12	0.9885	0.9959	1.0005	0.0057108	0.9873	0.99357	0.9973	0.0047451	-0.0032	-0.002325	-0.0012	0.00098446
1e+13	0.9883	0.99625	1.008	0.00842	0.9853	0.99295	1.005	0.0086149	-0.0043	-0.0033	-0.0029	0.00066833

Device Test: 28.19 VOLTAGE|OC/CS/12/12/0/0/5/1MHz//@V_CS_ILIM_OC





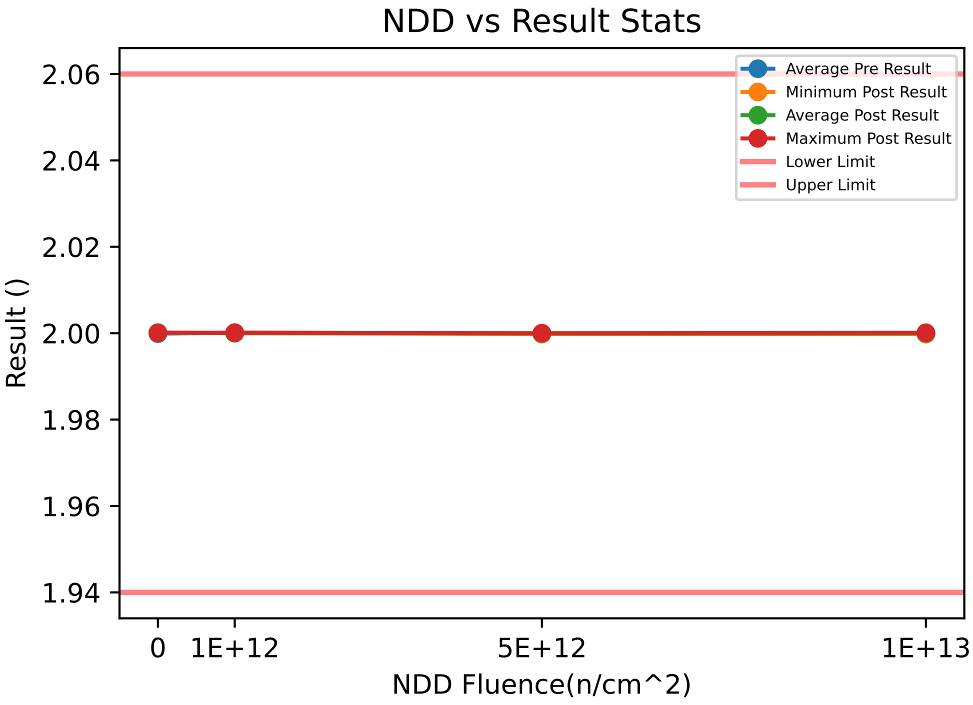
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

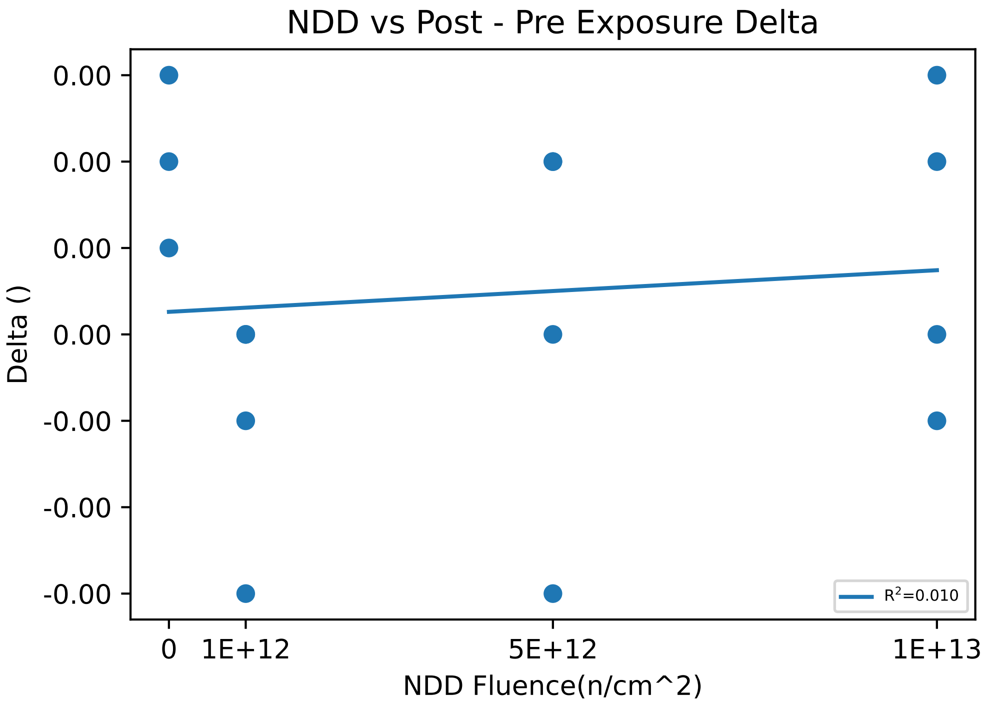
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.0003	0.999	-0.0013
2	1e+12	NDD	0.9943	0.9946	0.0003
3	1e+12	NDD	0.9912	0.9909	-0.0003
4	1e+12	NDD	0.9943	0.9928	-0.0015
5	5e+12	NDD	1.0004	0.9991	-0.0013
6	5e+12	NDD	1.0005	0.9989	-0.0016
7	5e+12	NDD	0.988	0.9871	-0.0009
8	5e+12	NDD	0.9958	0.9924	-0.0034
9	1e+13	NDD	0.9927	0.9886	-0.0041
10	1e+13	NDD	1.0076	1.0049	-0.0027
11	1e+13	NDD	0.9956	0.9928	-0.0028
12	1e+13	NDD	0.9884	0.9853	-0.0031
13	0	CORRELATION	0.9913	0.9916	0.0003
14	0	CORRELATION	0.9974	0.9974	0
15	0	CORRELATION	0.9914	0.9909	-0.0005

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9913	0.99337	0.9974	0.0034933	0.9909	0.9933	0.9974	0.0035679	-0.0005	-6.6667e-05	0.0003	0.00040415
1e+12	0.9912	0.99502	1.0003	0.0038082	0.9909	0.99433	0.999	0.0034635	-0.0015	-0.0007	0.0003	0.00084853
5e+12	0.988	0.99618	1.0005	0.0058745	0.9871	0.99438	0.9991	0.0057627	-0.0034	-0.0018	-0.0009	0.0011045
1e+13	0.9884	0.99608	1.0076	0.008233	0.9853	0.9929	1.0049	0.0085685	-0.0041	-0.003175	-0.0027	0.00063966

Device Test: 28.2 LEVEL|RATIO/CS/5/5/0/0/5/500kHz//@C_CS_R





Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

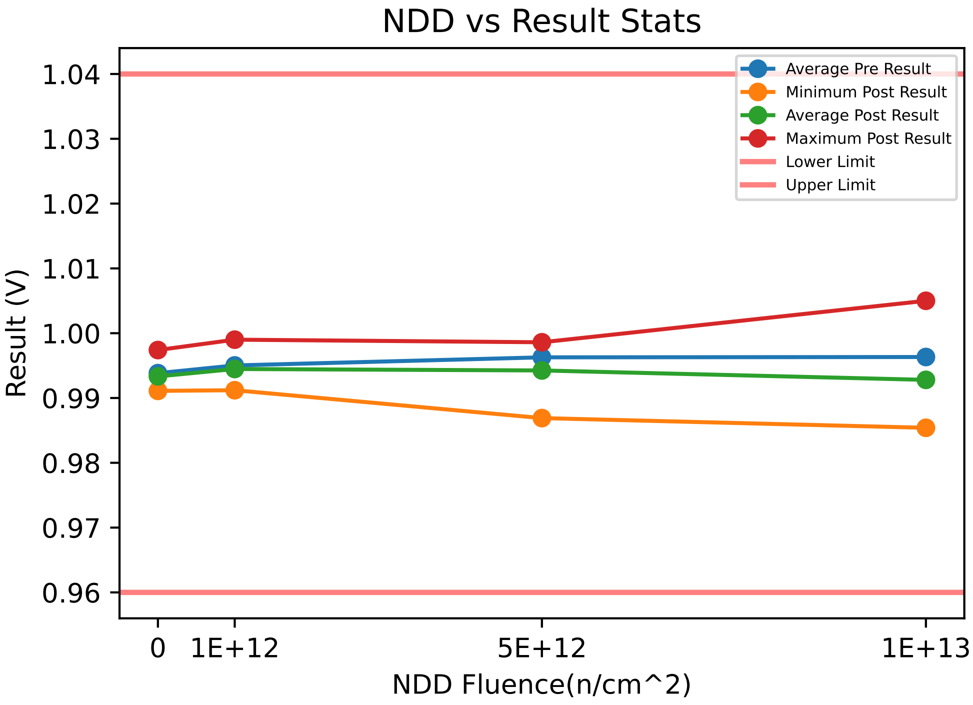
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2.0001	2	-0.0001
2	1e+12	NDD	2	2	0
3	1e+12	NDD	2.0001	2.0001	0
4	1e+12	NDD	2.0003	2	-0.0003
5	5e+12	NDD	2	2	0
6	5e+12	NDD	2.0001	1.9998	-0.0003
7	5e+12	NDD	1.9998	2	0.0002
8	5e+12	NDD	1.9998	2	0.0002
9	1e+13	NDD	1.9998	2	0.0002
10	1e+13	NDD	2	2	0
11	1e+13	NDD	1.9998	2.0001	0.0003
12	1e+13	NDD	1.9999	1.9998	-0.0001
13	0	CORRELATION	1.9999	2.0001	0.0002
14	0	CORRELATION	1.9998	2.0001	0.0003
15	0	CORRELATION	2	2.0001	0.0001

Test Statistics ()

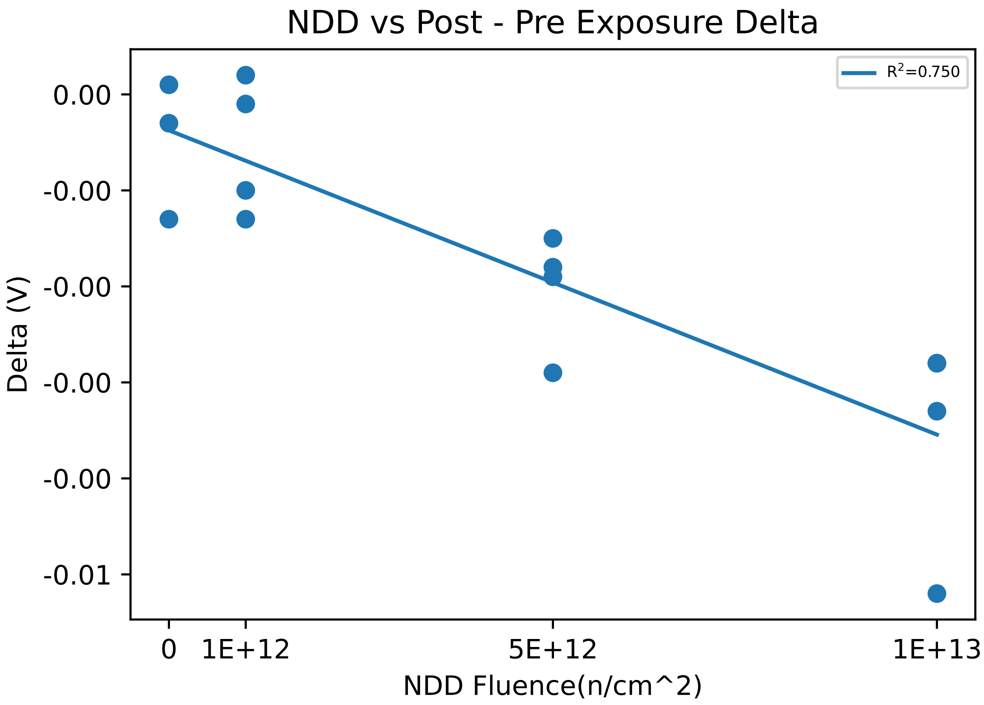
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9998	1.9999	2	0.0001	2.0001	2.0001	2.0001	0	0.0001	0.0002	0.0003	0.0001
1e+12	2	2.0001	2.0003	0.00012583	2	2	2.0001	5e-05	-0.0003	-0.0001	0	0.00014142
5e+12	1.9998	1.9999	2.0001	0.00015	1.9998	2	2	0.0001	-0.0003	2.5e-05	0.0002	0.00023629
1e+13	1.9998	1.9999	2	9.5743e-05	1.9998	2	2.0001	0.00012583	-0.0001	0.0001	0.0003	0.00018257

Device Test: 28.20 VOLTAGE|OC/CS/14/14/0/0/5/1MHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



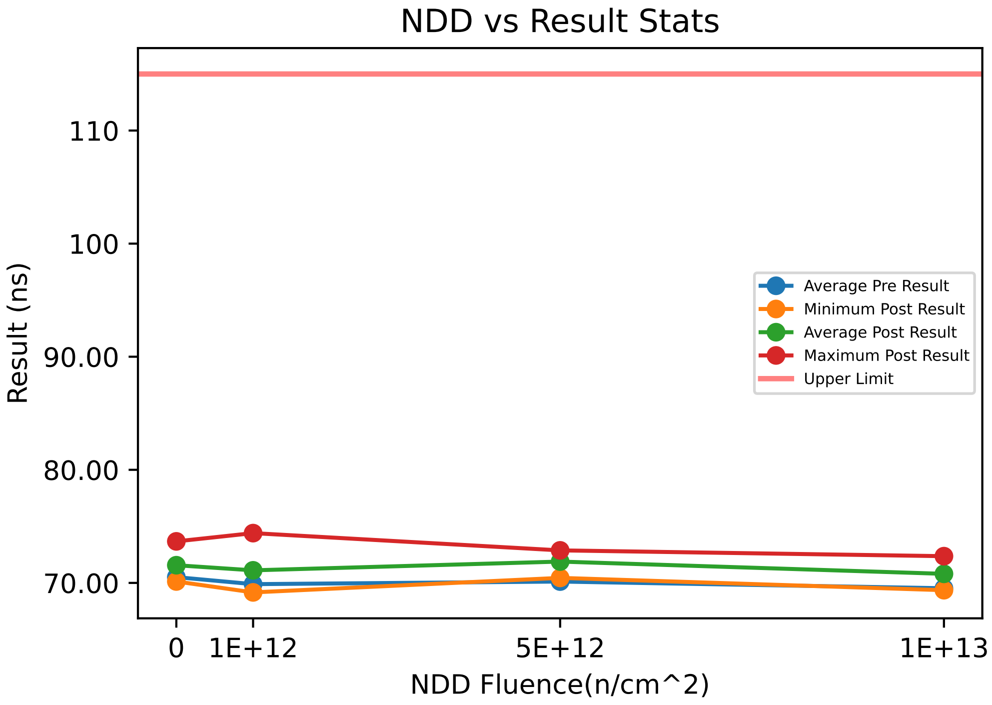
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

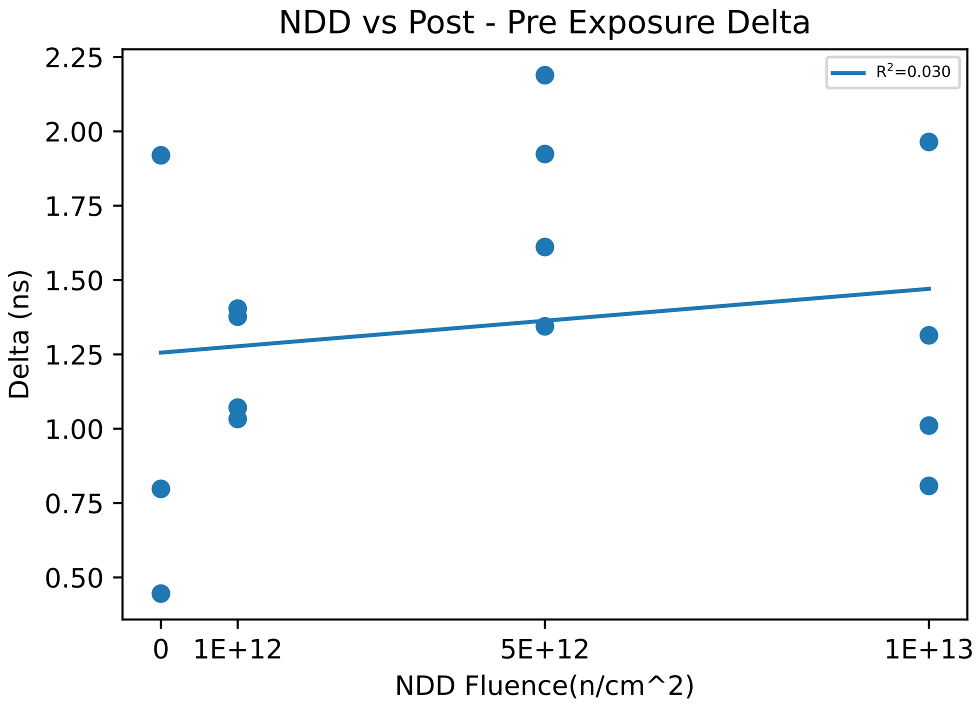
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.0003	0.999	-0.0013
2	1e+12	NDD	0.9942	0.9944	0.0002
3	1e+12	NDD	0.9913	0.9912	-0.0001
4	1e+12	NDD	0.9943	0.9933	-0.001
5	5e+12	NDD	1.0004	0.9986	-0.0018
6	5e+12	NDD	1.0005	0.9986	-0.0019
7	5e+12	NDD	0.9884	0.9869	-0.0015
8	5e+12	NDD	0.9958	0.9929	-0.0029
9	1e+13	NDD	0.993	0.9878	-0.0052
10	1e+13	NDD	1.0078	1.005	-0.0028
11	1e+13	NDD	0.9958	0.993	-0.0028
12	1e+13	NDD	0.9887	0.9854	-0.0033
13	0	CORRELATION	0.9928	0.9915	-0.0013
14	0	CORRELATION	0.9973	0.9974	0.0001
15	0	CORRELATION	0.9914	0.9911	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9914	0.99383	0.9973	0.0030827	0.9911	0.99333	0.9974	0.0035275	-0.0013	-0.0005	0.0001	0.00072111
1e+12	0.9913	0.99502	1.0003	0.0037819	0.9912	0.99447	0.999	0.0032958	-0.0013	-0.00055	0.0002	0.00071414
5e+12	0.9884	0.99628	1.0005	0.0056894	0.9869	0.99425	0.9986	0.0055884	-0.0029	-0.002025	-0.0015	0.00060759
1e+13	0.9887	0.99633	1.0078	0.0081884	0.9854	0.9928	1.005	0.00873	-0.0052	-0.003525	-0.0028	0.0011413

Device Test: 28.21 TIMING|DELAY/CS/4.5/4.5/0/0/4.5/100kHz//@CS_ILIM_DELAY





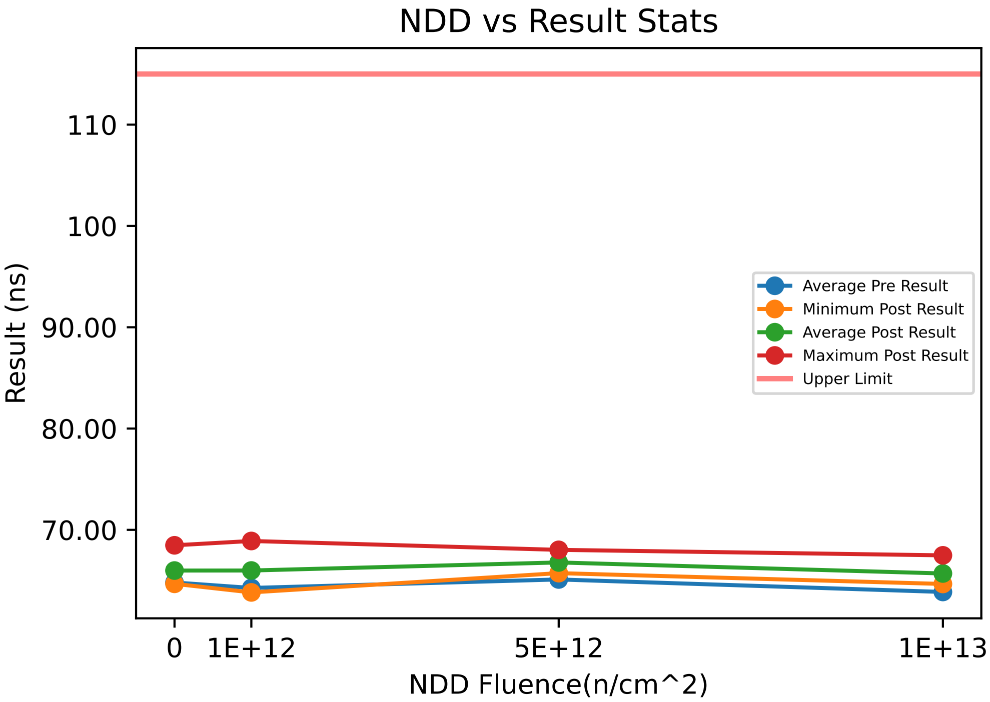
Test Results (Upper Limit = 115.0 (ns))

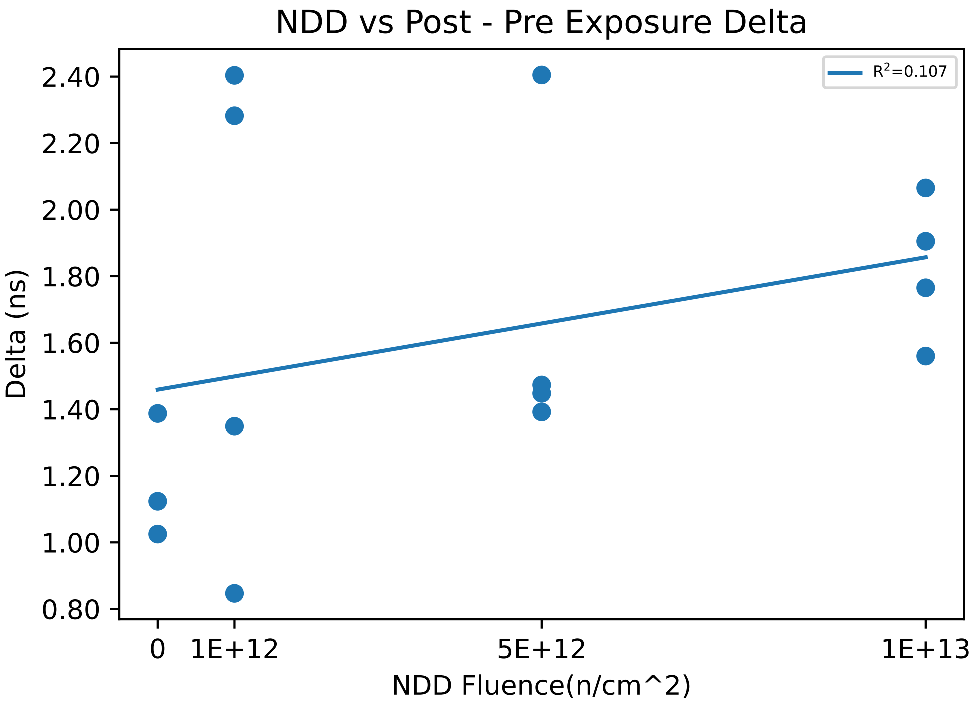
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	67.784	69.161	1.3767
2	1e+12	NDD	72.999	74.403	1.404
3	1e+12	NDD	70.602	71.634	1.0328
4	1e+12	NDD	68.177	69.248	1.071
5	5e+12	NDD	71.532	72.876	1.3444
6	5e+12	NDD	68.522	70.445	1.9238
7	5e+12	NDD	70.162	71.773	1.611
8	5e+12	NDD	70.262	72.451	2.1889
9	1e+13	NDD	69.264	71.228	1.9643
10	1e+13	NDD	68.549	69.356	0.8077
11	1e+13	NDD	71.05	72.364	1.3141
12	1e+13	NDD	69.248	70.259	1.0106
13	0	CORRELATION	69.328	70.126	0.7977
14	0	CORRELATION	73.227	73.672	0.4456
15	0	CORRELATION	68.973	70.893	1.9195

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	68.973	70.509	73.227	2.3598	70.126	71.564	73.672	1.8658	0.4456	1.0543	1.9195	0.76972
1e+12	67.784	69.89	72.999	2.4179	69.161	71.111	74.403	2.4754	1.0328	1.2211	1.404	0.19634
5e+12	68.522	70.119	71.532	1.2343	70.445	71.886	72.876	1.0626	1.3444	1.767	2.1889	0.36766
1e+13	68.549	69.528	71.05	1.0682	69.356	70.802	72.364	1.2918	0.8077	1.2742	1.9643	0.50495

Device Test: 28.22 TIMING|DELAY/CS/5/5/0/0/5/100kHz//@CS_ILIM_DELAY





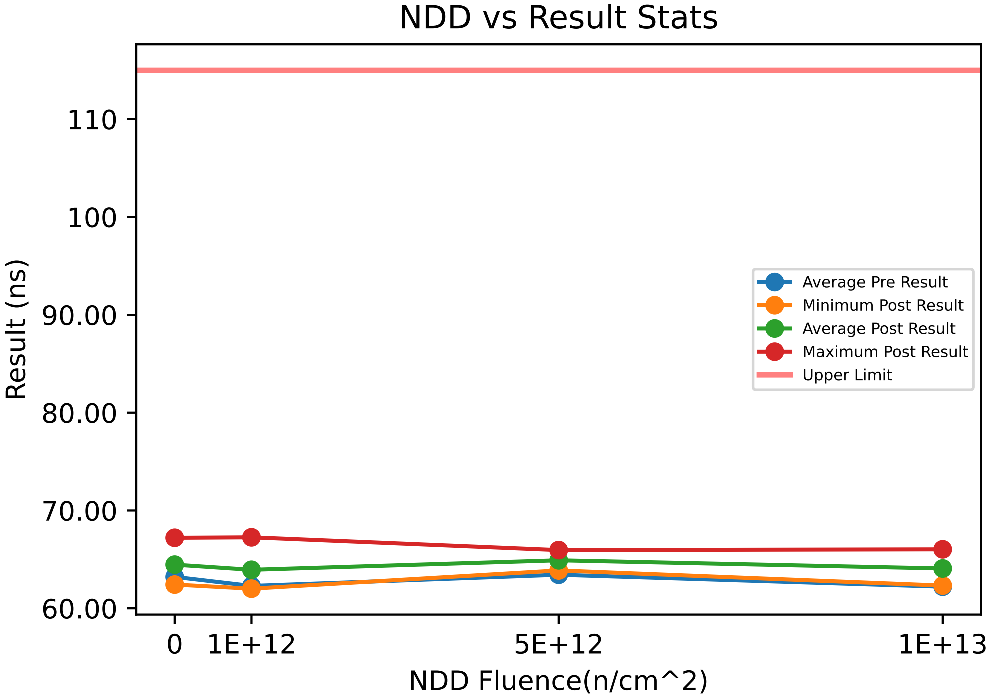
Test Results (Upper Limit = 115.0 (ns))

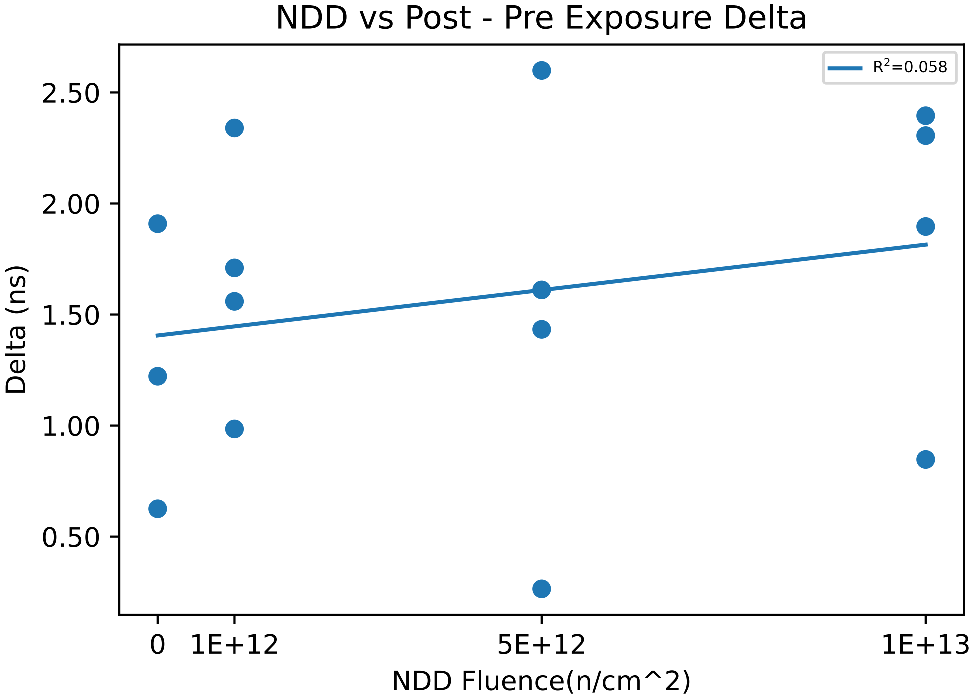
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.477	63.826	1.3492
2	1e+12	NDD	66.498	68.901	2.4037
3	1e+12	NDD	64.513	66.796	2.2823
4	1e+12	NDD	63.578	64.424	0.8468
5	5e+12	NDD	66.553	68.026	1.4732
6	5e+12	NDD	63.324	65.728	2.4049
7	5e+12	NDD	64.792	66.185	1.3923
8	5e+12	NDD	65.743	67.192	1.4482
9	1e+13	NDD	64.025	65.791	1.7652
10	1e+13	NDD	63.099	64.659	1.56
11	1e+13	NDD	65.419	67.484	2.0653
12	1e+13	NDD	62.937	64.842	1.905
13	0	CORRELATION	63.549	64.672	1.1235
14	0	CORRELATION	67.087	68.474	1.3877
15	0	CORRELATION	63.775	64.8	1.025

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.549	64.804	67.087	1.9803	64.672	65.982	68.474	2.159	1.025	1.1787	1.3877	0.18755
1e+12	62.477	64.266	66.498	1.7047	63.826	65.987	68.901	2.3282	0.8468	1.7205	2.4037	0.74913
5e+12	63.324	65.103	66.553	1.3874	65.728	66.783	68.026	1.0299	1.3923	1.6796	2.4049	0.48468
1e+13	62.937	63.87	65.419	1.1385	64.659	65.694	67.484	1.2924	1.56	1.8239	2.0653	0.21443

Device Test: 28.23 TIMING|DELAY/CS/12/12/0/0/5/100kHz//@CS_ILIM_DELAY





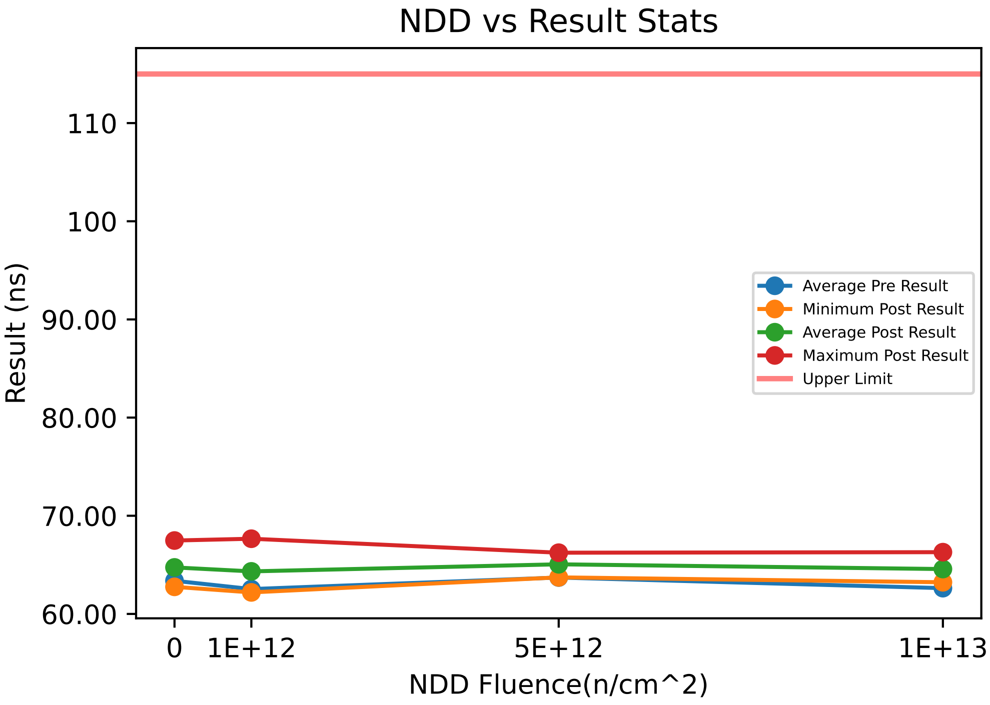
Test Results (Upper Limit = 115.0 (ns))

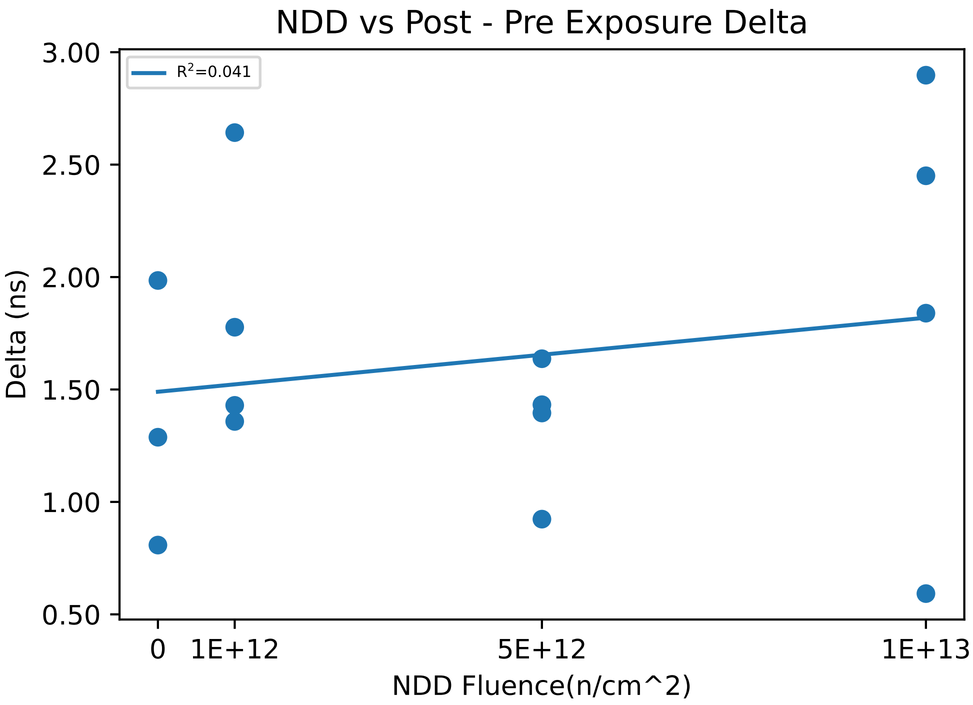
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60.51	62.069	1.5593
2	1e+12	NDD	64.917	67.257	2.34
3	1e+12	NDD	62.709	64.419	1.71
4	1e+12	NDD	61.025	62.009	0.9848
5	5e+12	NDD	64.519	65.952	1.4332
6	5e+12	NDD	61.486	64.085	2.5991
7	5e+12	NDD	63.607	63.872	0.2647
8	5e+12	NDD	64.114	65.725	1.6109
9	1e+13	NDD	62.299	64.195	1.8963
10	1e+13	NDD	61.477	62.325	0.8473
11	1e+13	NDD	63.633	66.029	2.3953
12	1e+13	NDD	61.437	63.743	2.3057
13	0	CORRELATION	61.802	62.427	0.6253
14	0	CORRELATION	65.301	67.21	1.909
15	0	CORRELATION	62.531	63.753	1.222

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.802	63.211	65.301	1.8459	62.427	64.463	67.21	2.4691	0.6253	1.2521	1.909	0.64238
1e+12	60.51	62.29	64.917	1.987	62.009	63.939	67.257	2.4803	0.9848	1.6485	2.34	0.5569
5e+12	61.486	63.431	64.519	1.3495	63.872	64.908	65.952	1.0812	0.2647	1.477	2.5991	0.95719
1e+13	61.437	62.212	63.633	1.0277	62.325	64.073	66.029	1.5281	0.8473	1.8611	2.3953	0.70995

Device Test: 28.24 TIMING|DELAY/CS/14/14/0/0/5/100kHz//@CS_ILIM_DELAY


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

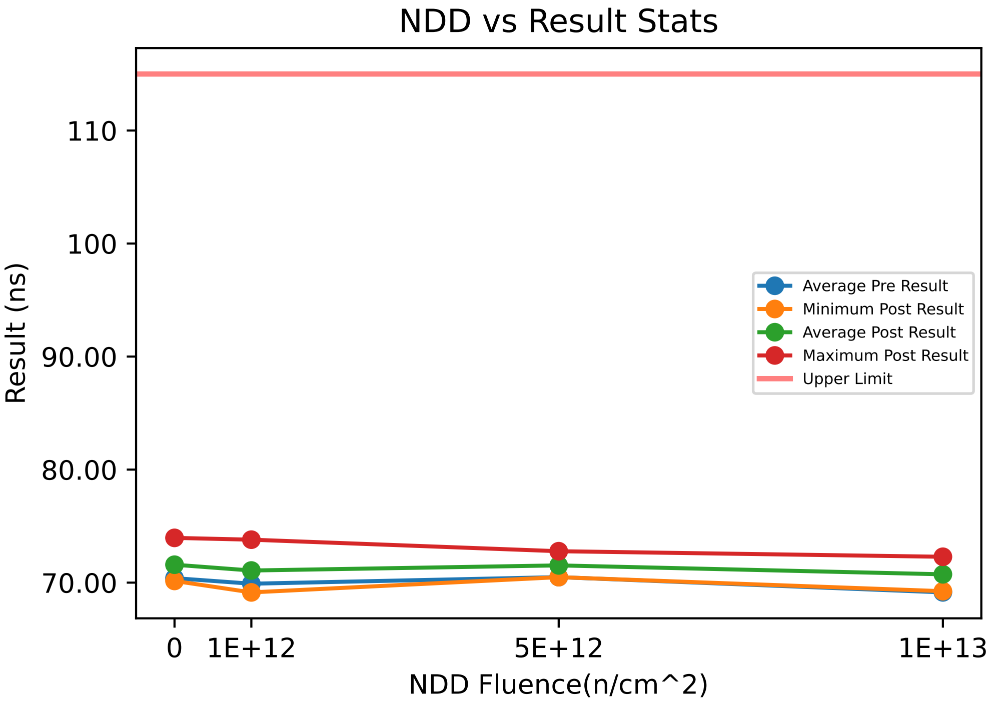
Test Results (Upper Limit = 115.0 (ns))

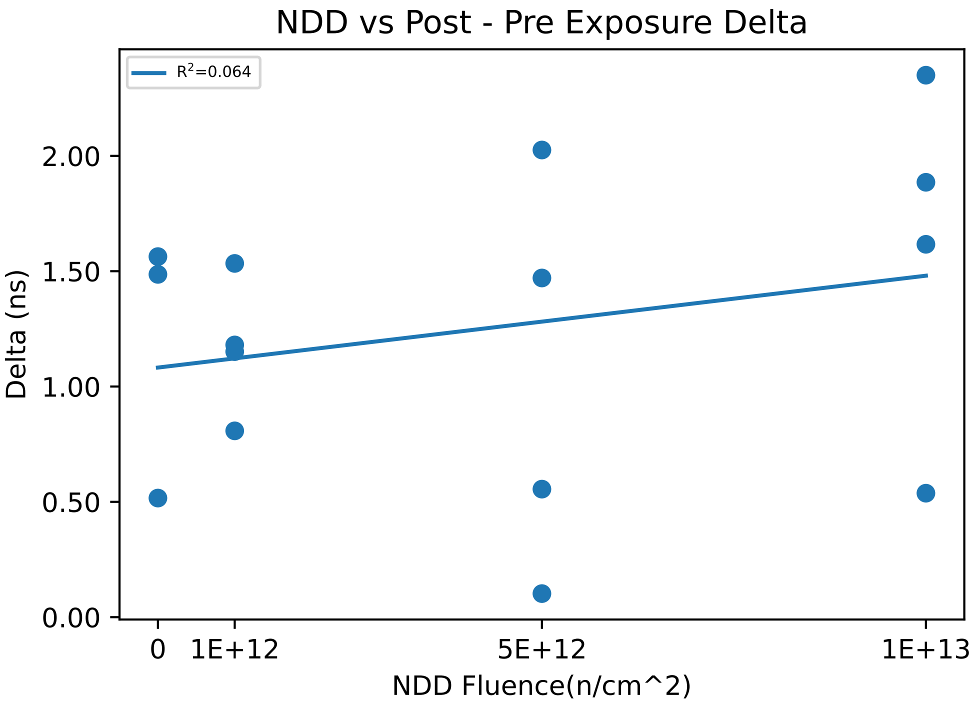
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60.764	62.194	1.4294
2	1e+12	NDD	65.018	67.66	2.6424
3	1e+12	NDD	62.876	64.653	1.7769
4	1e+12	NDD	61.474	62.832	1.3579
5	5e+12	NDD	64.841	66.237	1.3955
6	5e+12	NDD	62.293	63.726	1.4323
7	5e+12	NDD	63.339	64.263	0.9234
8	5e+12	NDD	64.36	65.997	1.6368
9	1e+13	NDD	62.06	64.51	2.4504
10	1e+13	NDD	62.635	63.227	0.5923
11	1e+13	NDD	64.452	66.291	1.8394
12	1e+13	NDD	61.361	64.259	2.8977
13	0	CORRELATION	61.952	62.76	0.8081
14	0	CORRELATION	66.189	67.477	1.2877
15	0	CORRELATION	61.993	63.978	1.9848

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.952	63.378	66.189	2.4346	62.76	64.738	67.477	2.4486	0.8081	1.3602	1.9848	0.59169
1e+12	60.764	62.533	65.018	1.8747	62.194	64.335	67.66	2.4498	1.3579	1.8016	2.6424	0.58962
5e+12	62.293	63.709	64.841	1.1325	63.726	65.056	66.237	1.249	0.9234	1.347	1.6368	0.30169
1e+13	61.361	62.627	64.452	1.3234	63.227	64.572	66.291	1.2736	0.5923	1.945	2.8977	1.0007

Device Test: 28.25 TIMING|DELAY/CS/4.5/4.5/0/0/4.5/500kHz//@CS_ILIM_DELAY





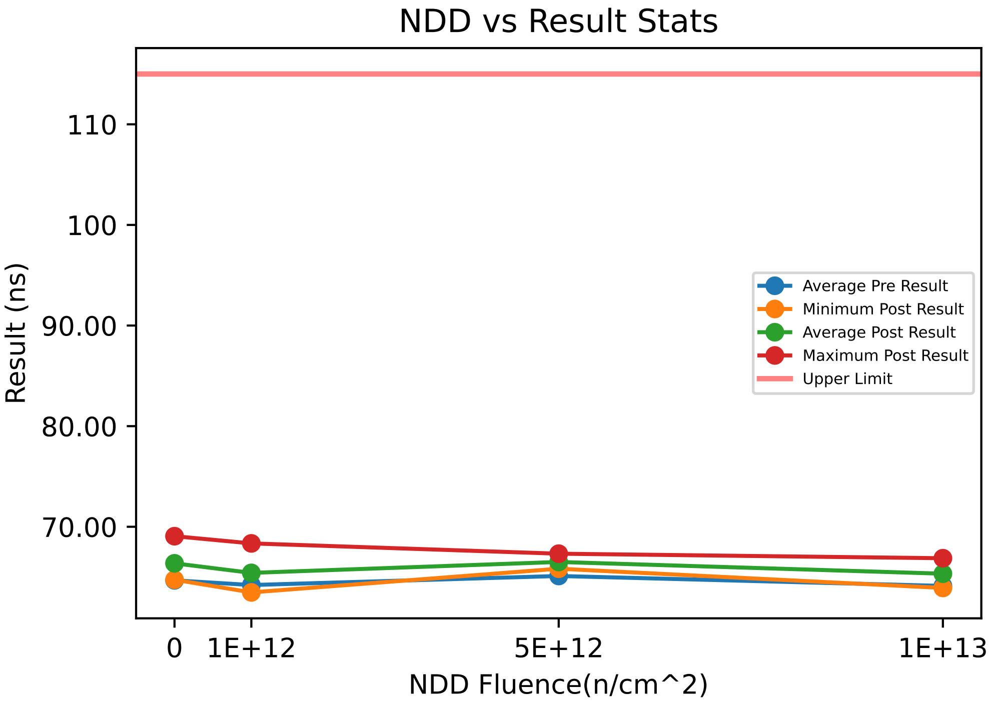
Test Results (Upper Limit = 115.0 (ns))

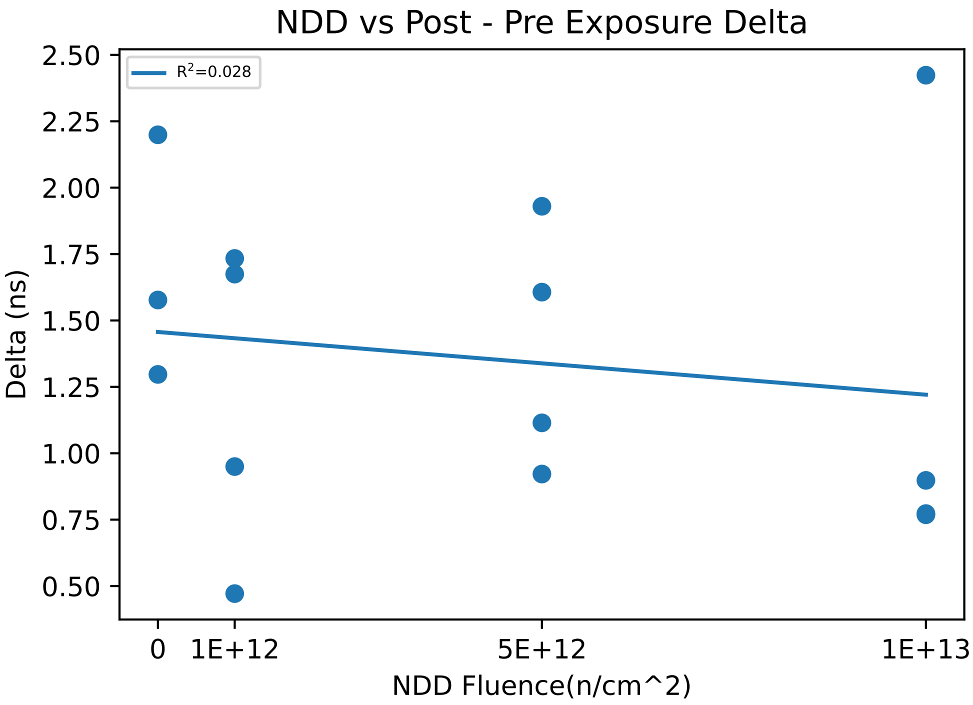
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	67.603	69.136	1.5337
2	1e+12	NDD	72.62	73.801	1.1803
3	1e+12	NDD	70.498	71.649	1.1513
4	1e+12	NDD	68.899	69.707	0.8078
5	5e+12	NDD	72.225	72.78	0.5551
6	5e+12	NDD	68.459	70.484	2.0255
7	5e+12	NDD	70.946	71.049	0.1022
8	5e+12	NDD	70.319	71.79	1.4706
9	1e+13	NDD	68.693	70.579	1.8855
10	1e+13	NDD	68.705	69.243	0.5375
11	1e+13	NDD	70.672	72.289	1.6166
12	1e+13	NDD	68.487	70.836	2.3498
13	0	CORRELATION	68.664	70.15	1.4862
14	0	CORRELATION	73.444	73.96	0.5164
15	0	CORRELATION	69.082	70.645	1.5633

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	68.664	70.397	73.444	2.6473	70.15	71.585	73.96	2.0717	0.5164	1.1886	1.5633	0.58345
1e+12	67.603	69.905	72.62	2.1632	69.136	71.073	73.801	2.1127	0.8078	1.1683	1.5337	0.2966
5e+12	68.459	70.487	72.225	1.5678	70.484	71.526	72.78	0.99258	0.1022	1.0384	2.0255	0.8701
1e+13	68.487	69.139	70.672	1.0268	69.243	70.737	72.289	1.2483	0.5375	1.5974	2.3498	0.76874

Device Test: 28.26 TIMING|DELAY/CS/5/5/0/0/5/500kHz//@CS_ILIM_DELAY


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

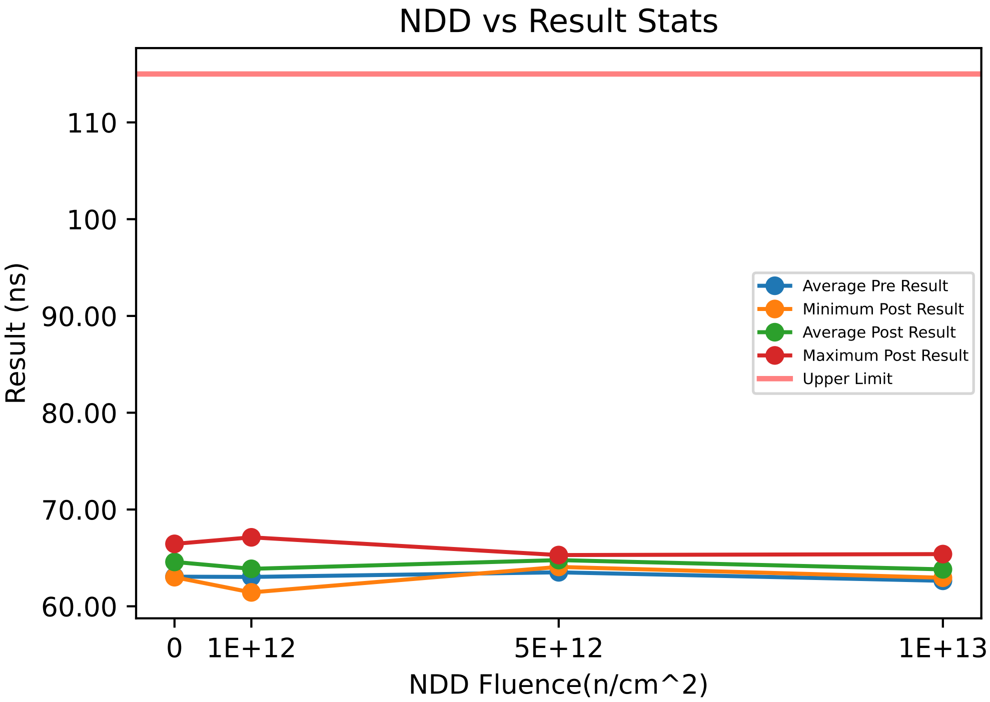
Test Results (Upper Limit = 115.0 (ns))

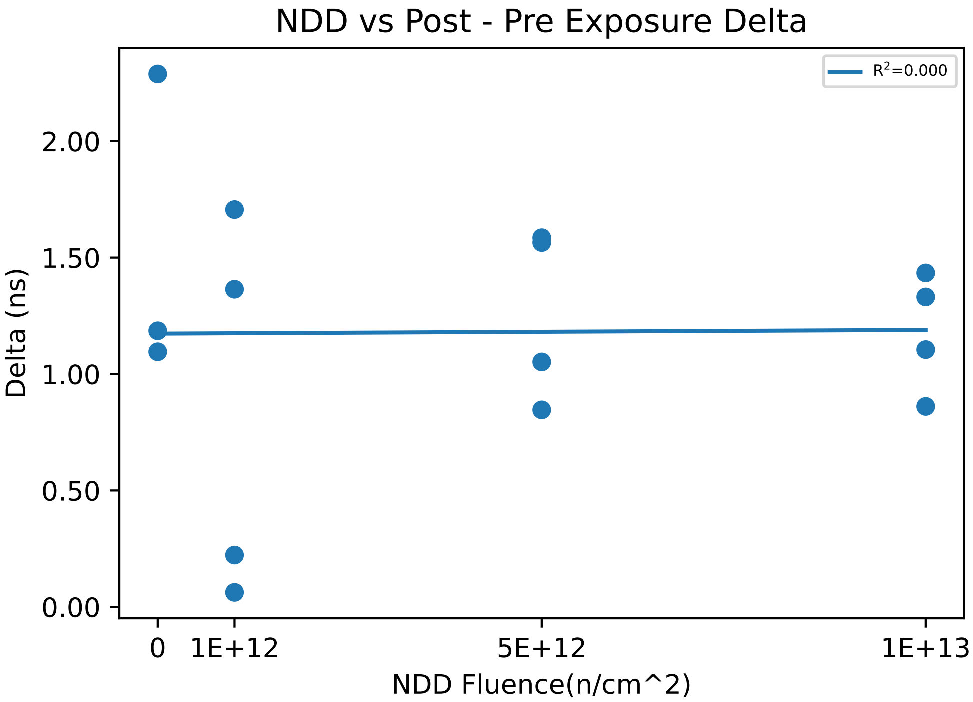
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	63.006	63.477	0.4716
2	1e+12	NDD	66.674	68.349	1.6745
3	1e+12	NDD	64.306	66.04	1.7335
4	1e+12	NDD	62.851	63.801	0.9499
5	5e+12	NDD	66.403	67.324	0.9218
6	5e+12	NDD	63.902	65.832	1.93
7	5e+12	NDD	64.703	66.31	1.6067
8	5e+12	NDD	65.429	66.543	1.1145
9	1e+13	NDD	63.469	65.892	2.4235
10	1e+13	NDD	63.151	63.92	0.7684
11	1e+13	NDD	66.101	66.874	0.7729
12	1e+13	NDD	63.764	64.661	0.8979
13	0	CORRELATION	63.441	64.737	1.2969
14	0	CORRELATION	66.864	69.063	2.1991
15	0	CORRELATION	63.723	65.3	1.5771

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.441	64.676	66.864	1.9004	64.737	66.367	69.063	2.352	1.2969	1.691	2.1991	0.46176
1e+12	62.851	64.209	66.674	1.768	63.477	65.417	68.349	2.2624	0.4716	1.2074	1.7335	0.60626
5e+12	63.902	65.109	66.403	1.0642	65.832	66.502	67.324	0.6229	0.9218	1.3933	1.93	0.45958
1e+13	63.151	64.121	66.101	1.3432	63.92	65.337	66.874	1.3082	0.7684	1.2157	2.4235	0.80745

Device Test: 28.27 TIMING|DELAY/CS/12/12/0/0/5/500kHz//@CS_ILIM_DELAY





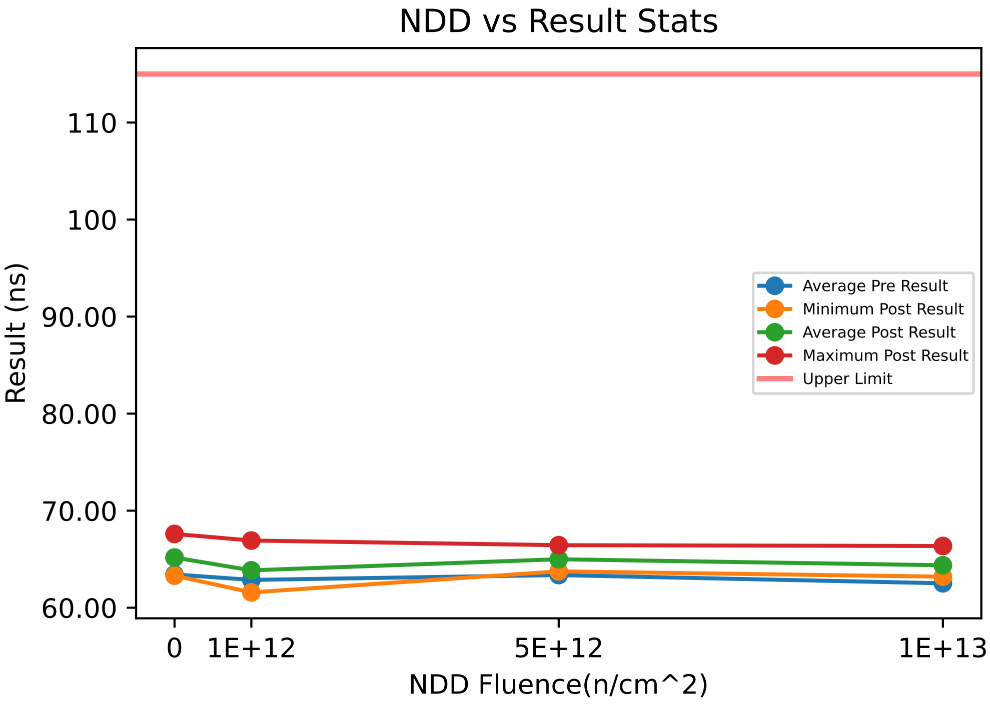
Test Results (Upper Limit = 115.0 (ns))

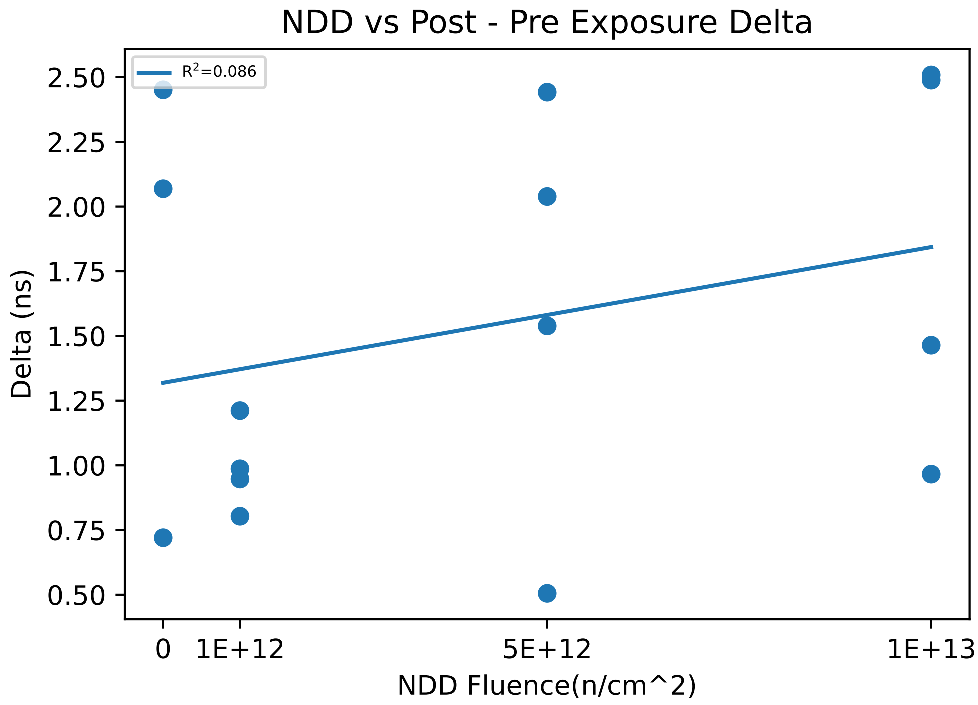
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.212	61.435	0.2226
2	1e+12	NDD	65.761	67.125	1.3641
3	1e+12	NDD	63.335	65.042	1.7062
4	1e+12	NDD	61.821	61.883	0.0623
5	5e+12	NDD	64.447	65.293	0.8461
6	5e+12	NDD	62.503	64.067	1.5647
7	5e+12	NDD	62.988	64.573	1.5854
8	5e+12	NDD	64.101	65.153	1.052
9	1e+13	NDD	62.385	63.716	1.331
10	1e+13	NDD	62.087	62.948	0.8609
11	1e+13	NDD	63.958	65.392	1.4341
12	1e+13	NDD	62.099	63.203	1.1049
13	0	CORRELATION	61.821	63.007	1.1857
14	0	CORRELATION	65.353	66.448	1.0956
15	0	CORRELATION	62.003	64.292	2.2886

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.821	63.059	65.353	1.9884	63.007	64.582	66.448	1.7389	1.0956	1.5233	2.2886	0.6643
1e+12	61.212	63.032	65.761	2.0262	61.435	63.871	67.125	2.6984	0.0623	0.8388	1.7062	0.81873
5e+12	62.503	63.51	64.447	0.91549	64.067	64.772	65.293	0.5635	0.8461	1.2621	1.5854	0.37116
1e+13	62.087	62.632	63.958	0.89448	62.948	63.815	65.392	1.0988	0.8609	1.1827	1.4341	0.25482

Device Test: 28.28 TIMING|DELAY/CS/14/14/0/0/5/500kHz//@CS_ILIM_DELAY





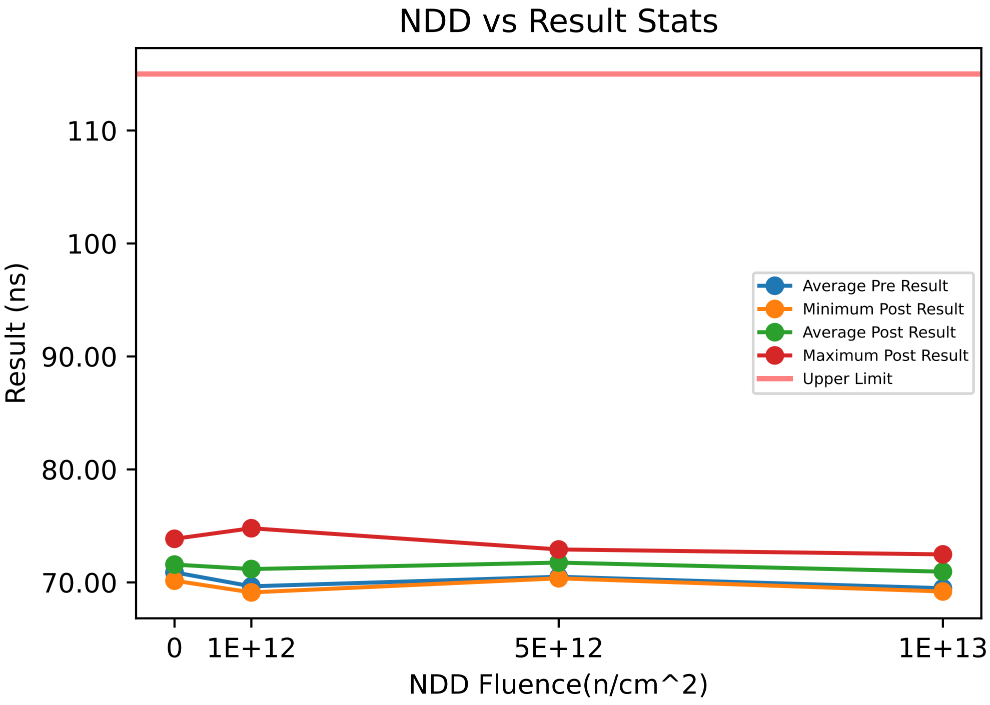
Test Results (Upper Limit = 115.0 (ns))

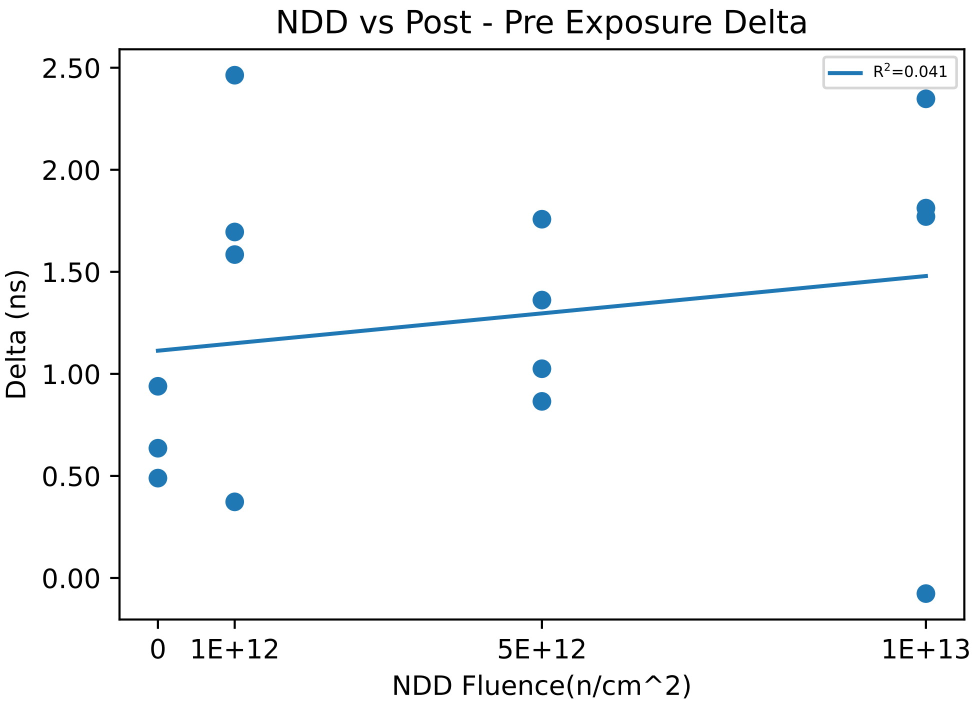
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60.775	61.578	0.8033
2	1e+12	NDD	65.976	66.923	0.9471
3	1e+12	NDD	63.426	64.637	1.2114
4	1e+12	NDD	61.294	62.28	0.9866
5	5e+12	NDD	64.001	66.443	2.4421
6	5e+12	NDD	61.708	63.747	2.0389
7	5e+12	NDD	63.776	64.281	0.5053
8	5e+12	NDD	63.967	65.506	1.5387
9	1e+13	NDD	62.885	63.851	0.966
10	1e+13	NDD	61.733	63.197	1.4642
11	1e+13	NDD	63.872	66.361	2.4886
12	1e+13	NDD	61.579	64.087	2.5086
13	0	CORRELATION	62.588	63.308	0.7203
14	0	CORRELATION	65.536	67.605	2.0689
15	0	CORRELATION	62.156	64.608	2.4512

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.156	63.427	65.536	1.8392	63.308	65.174	67.605	2.2033	0.7203	1.7468	2.4512	0.90929
1e+12	60.775	62.868	65.976	2.3685	61.578	63.855	66.923	2.4282	0.8033	0.9871	1.2114	0.16901
5e+12	61.708	63.363	64.001	1.1079	63.747	64.994	66.443	1.2146	0.5053	1.6312	2.4421	0.83666
1e+13	61.579	62.517	63.872	1.075	63.197	64.374	66.361	1.3768	0.966	1.8568	2.5086	0.76848

Device Test: 28.29 TIMING|DELAY/CS/4.5/4.5/0/0/4.5/1MHz//@CS_ILIM_DELAY





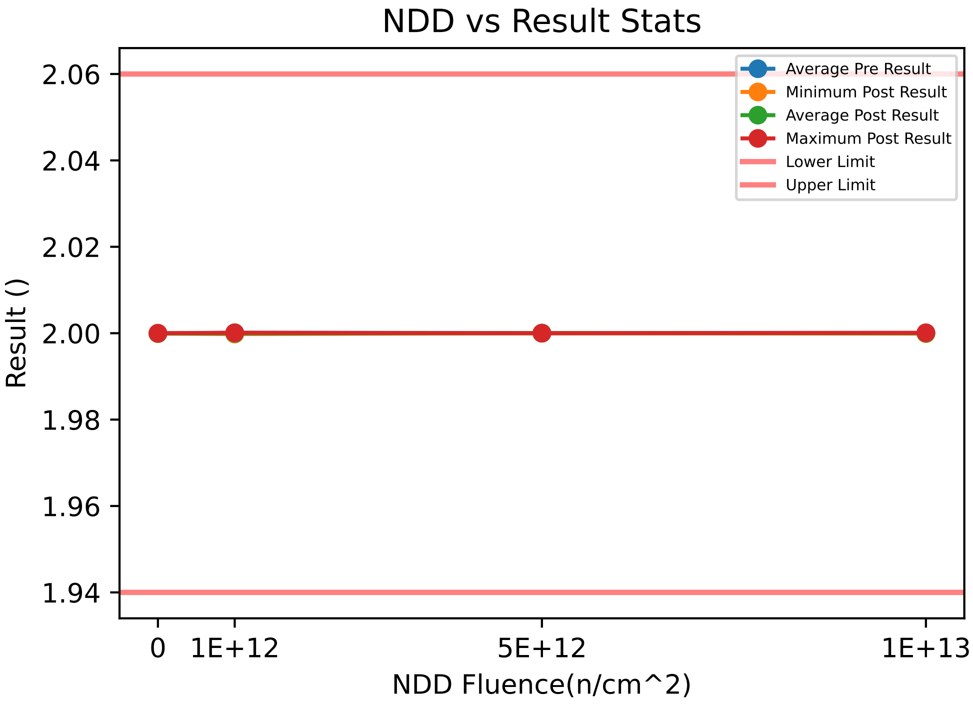
Test Results (Upper Limit = 115.0 (ns))

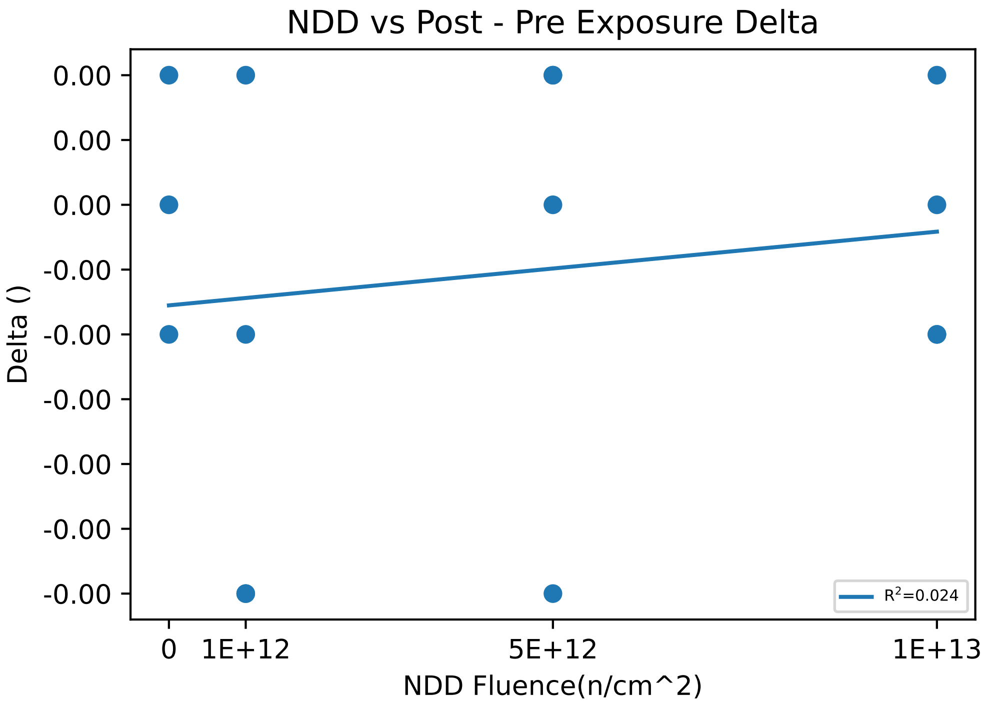
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	67.531	69.116	1.5846
2	1e+12	NDD	72.33	74.794	2.4635
3	1e+12	NDD	69.894	71.589	1.6953
4	1e+12	NDD	68.858	69.231	0.373
5	5e+12	NDD	71.556	72.918	1.3616
6	5e+12	NDD	68.606	70.364	1.7579
7	5e+12	NDD	71.167	72.033	0.8653
8	5e+12	NDD	70.673	71.698	1.0252
9	1e+13	NDD	68.93	71.278	2.3477
10	1e+13	NDD	69.273	69.197	-0.0765
11	1e+13	NDD	70.71	72.481	1.7709
12	1e+13	NDD	69.037	70.849	1.8122
13	0	CORRELATION	69.665	70.154	0.4893
14	0	CORRELATION	73.223	73.859	0.6358
15	0	CORRELATION	69.785	70.725	0.9393

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.665	70.891	73.223	2.0204	70.154	71.579	73.859	1.9947	0.4893	0.68813	0.9393	0.22952
1e+12	67.531	69.653	72.33	2.0298	69.116	71.182	74.794	2.6637	0.373	1.5291	2.4635	0.86417
5e+12	68.606	70.501	71.556	1.3137	70.364	71.753	72.918	1.0594	0.8653	1.2525	1.7579	0.39536
1e+13	68.93	69.487	70.71	0.82738	69.197	70.951	72.481	1.3581	-0.0765	1.4636	2.3477	1.0598

Device Test: 28.3 LEVEL|RATIO/CS/12/12/0/0/5/500kHz//@C_CS_R





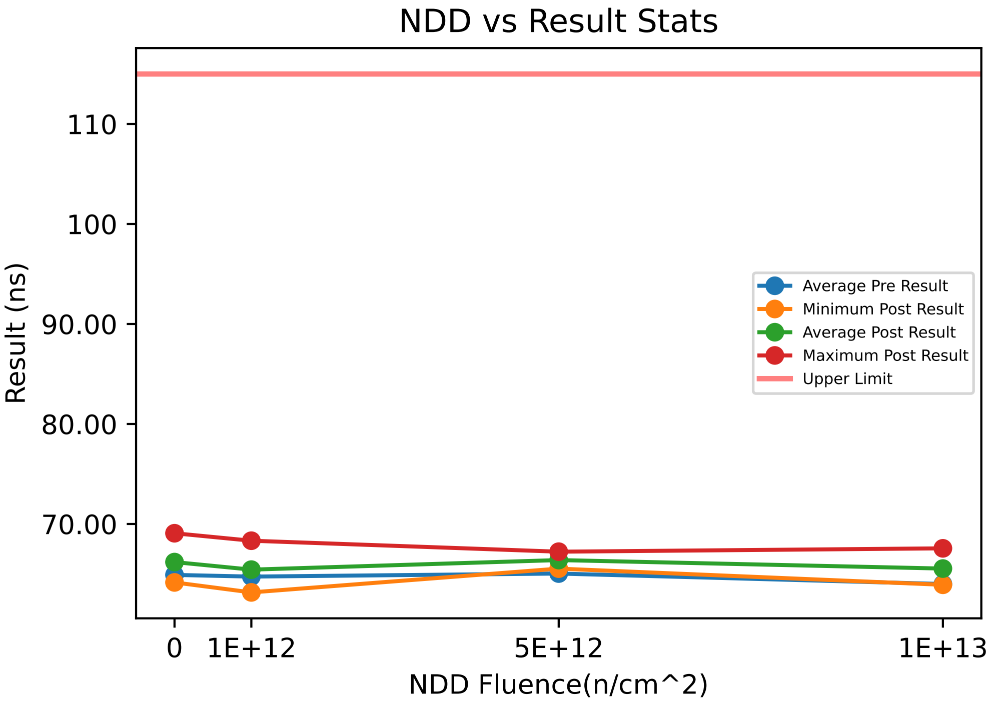
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

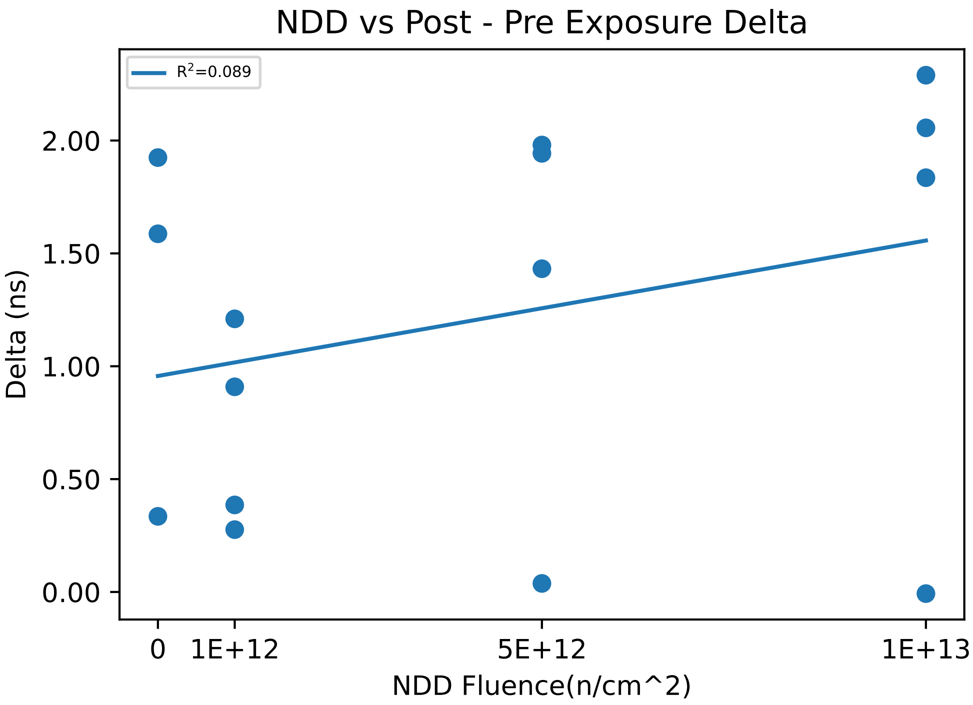
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2	2.0001	0.0001
2	1e+12	NDD	2.0001	2	-0.0001
3	1e+12	NDD	2.0001	1.9998	-0.0003
4	1e+12	NDD	2.0002	1.9999	-0.0003
5	5e+12	NDD	2	2	0
6	5e+12	NDD	1.9999	2	0.0001
7	5e+12	NDD	2.0003	2	-0.0003
8	5e+12	NDD	1.9999	2	0.0001
9	1e+13	NDD	2.0001	2	-0.0001
10	1e+13	NDD	2	2.0001	0.0001
11	1e+13	NDD	1.9999	1.9999	0
12	1e+13	NDD	2.0001	2	-0.0001
13	0	CORRELATION	2	2	0
14	0	CORRELATION	2	1.9999	-0.0001
15	0	CORRELATION	1.9998	1.9999	0.0001

Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9998	1.9999	2	0.00011547	1.9999	1.9999	2	5.7735e-05	-0.0001	0	0.0001	0.0001
1e+12	2	2.0001	2.0002	8.165e-05	1.9998	2	2.0001	0.0001291	-0.0003	-0.00015	0.0001	0.00019149
5e+12	1.9999	2	2.0003	0.0001893	2	2	2	0	-0.0003	-2.5e-05	0.0001	0.0001893
1e+13	1.9999	2	2.0001	9.5743e-05	1.9999	2	2.0001	8.165e-05	-0.0001	-2.5e-05	0.0001	9.5743e-05

Device Test: 28.30 TIMING|DELAY/CS/5/5/0/0/5/1MHz//@CS_ILIM_DELAY





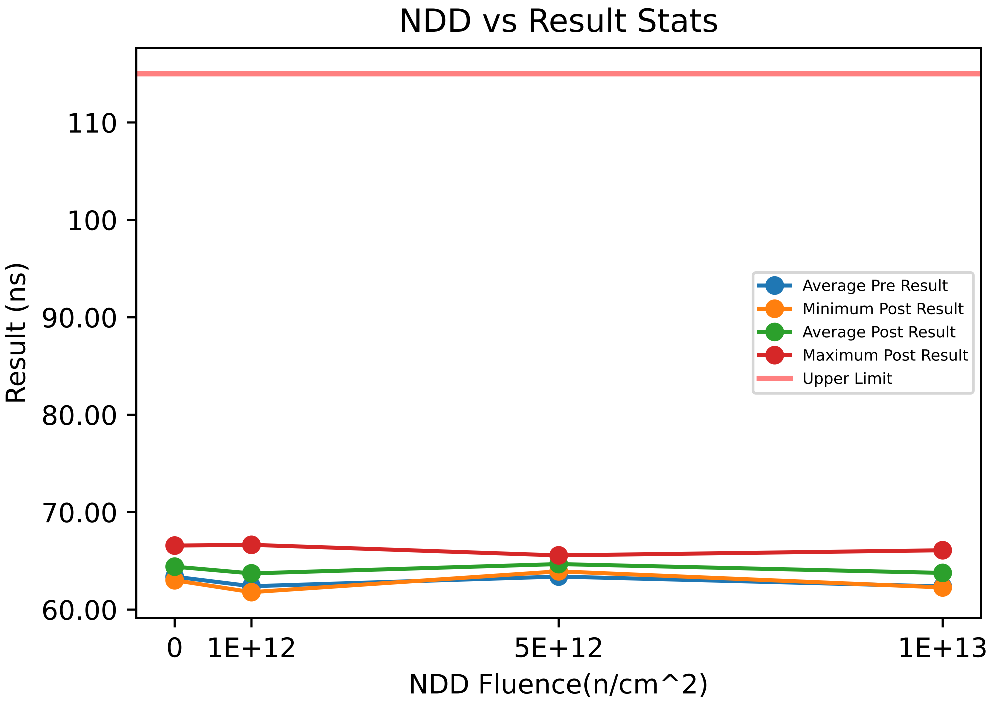
Test Results (Upper Limit = 115.0 (ns))

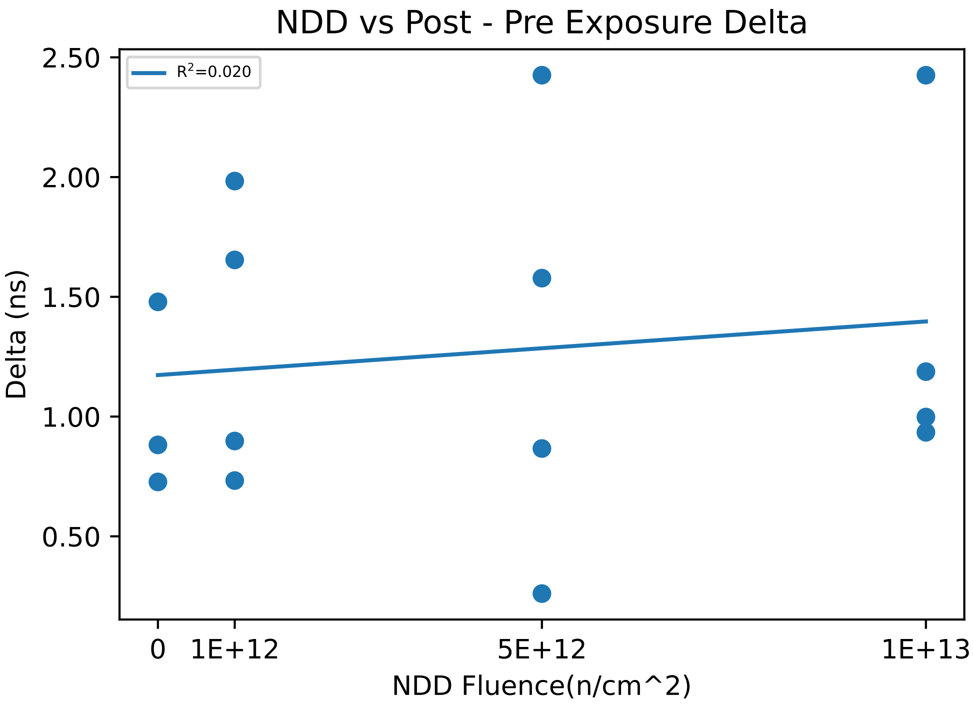
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.883	63.159	0.2762
2	1e+12	NDD	67.419	68.328	0.9089
3	1e+12	NDD	65.01	66.22	1.21
4	1e+12	NDD	63.649	64.035	0.3856
5	5e+12	NDD	65.798	67.23	1.432
6	5e+12	NDD	63.87	65.85	1.9801
7	5e+12	NDD	65.499	65.536	0.0379
8	5e+12	NDD	65.008	66.951	1.9431
9	1e+13	NDD	63.445	65.734	2.2894
10	1e+13	NDD	63.928	63.921	-0.0072
11	1e+13	NDD	65.509	67.565	2.0561
12	1e+13	NDD	63.114	64.949	1.8353
13	0	CORRELATION	63.822	64.156	0.335
14	0	CORRELATION	67.15	69.074	1.9244
15	0	CORRELATION	63.754	65.341	1.5868

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.754	64.908	67.15	1.9415	64.156	66.191	69.074	2.5667	0.335	1.2821	1.9244	0.83737
1e+12	62.883	64.74	67.419	1.9906	63.159	65.435	68.328	2.3183	0.2762	0.69518	1.21	0.44049
5e+12	63.87	65.044	65.798	0.84753	65.536	66.392	67.23	0.82484	0.0379	1.3483	1.9801	0.90868
1e+13	63.114	63.999	65.509	1.0607	63.921	65.542	67.565	1.5395	-0.0072	1.5434	2.2894	1.0502

Device Test: 28.31 TIMING|DELAY/CS/12/12/0/0/5/1MHz//@CS_ILIM_DELAY





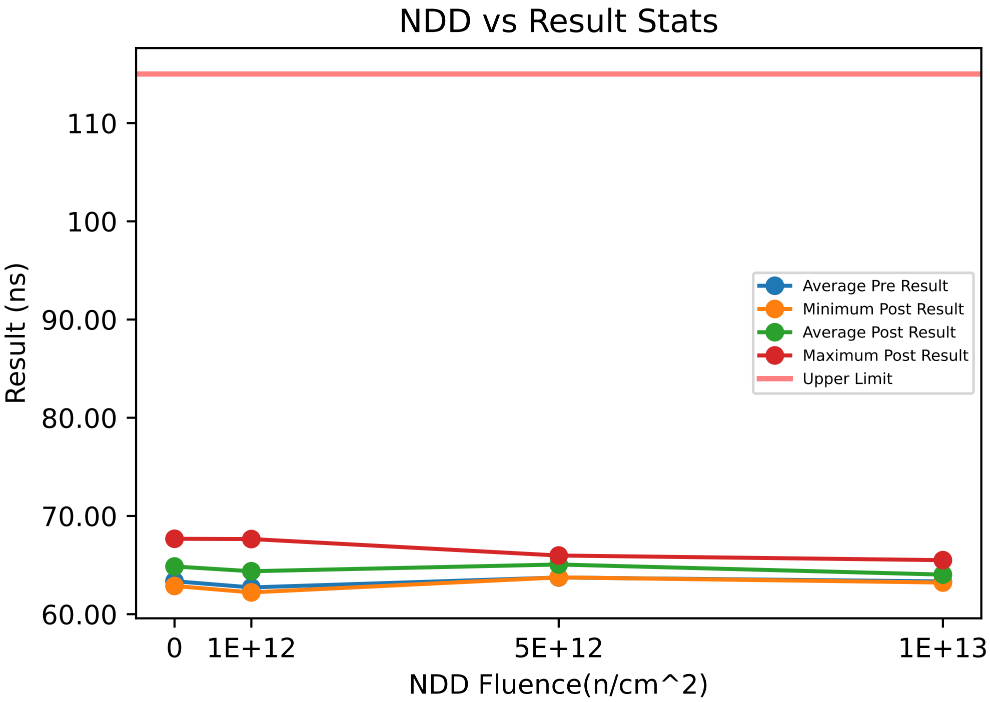
Test Results (Upper Limit = 115.0 (ns))

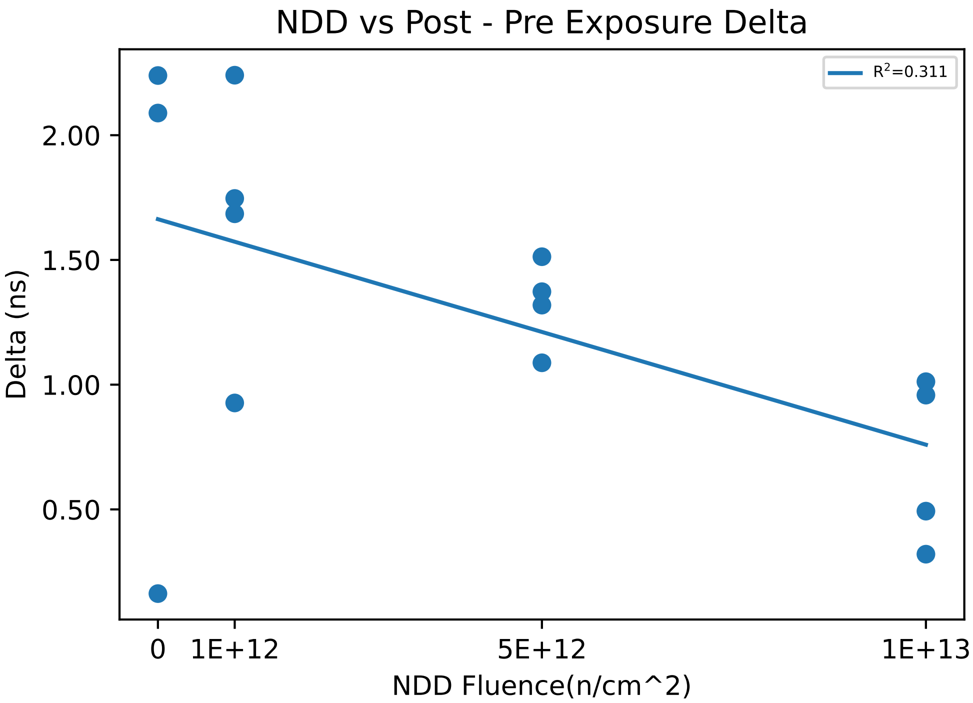
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.2	62.098	0.898
2	1e+12	NDD	64.992	66.647	1.6542
3	1e+12	NDD	62.345	64.328	1.9834
4	1e+12	NDD	61.058	61.791	0.7329
5	5e+12	NDD	63.984	65.563	1.5781
6	5e+12	NDD	61.614	64.04	2.4254
7	5e+12	NDD	63.666	63.927	0.2609
8	5e+12	NDD	64.293	65.16	0.8667
9	1e+13	NDD	62.494	63.492	0.9981
10	1e+13	NDD	61.338	62.272	0.9342
11	1e+13	NDD	63.666	66.091	2.4253
12	1e+13	NDD	62.016	63.204	1.1877
13	0	CORRELATION	62.282	63.009	0.7271
14	0	CORRELATION	65.092	66.571	1.4791
15	0	CORRELATION	62.757	63.639	0.8818

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.282	63.377	65.092	1.5041	63.009	64.406	66.571	1.901	0.7271	1.0293	1.4791	0.39712
1e+12	61.058	62.399	64.992	1.8225	61.791	63.716	66.647	2.2574	0.7329	1.3171	1.9834	0.59848
5e+12	61.614	63.389	64.293	1.2108	63.927	64.672	65.563	0.81374	0.2609	1.2828	2.4254	0.93277
1e+13	61.338	62.378	63.666	0.98047	62.272	63.765	66.091	1.6358	0.9342	1.3863	2.4253	0.70097

Device Test: 28.32 TIMING|DELAY/CS/14/14/0/0/5/1MHz//@CS_ILIM_DELAY





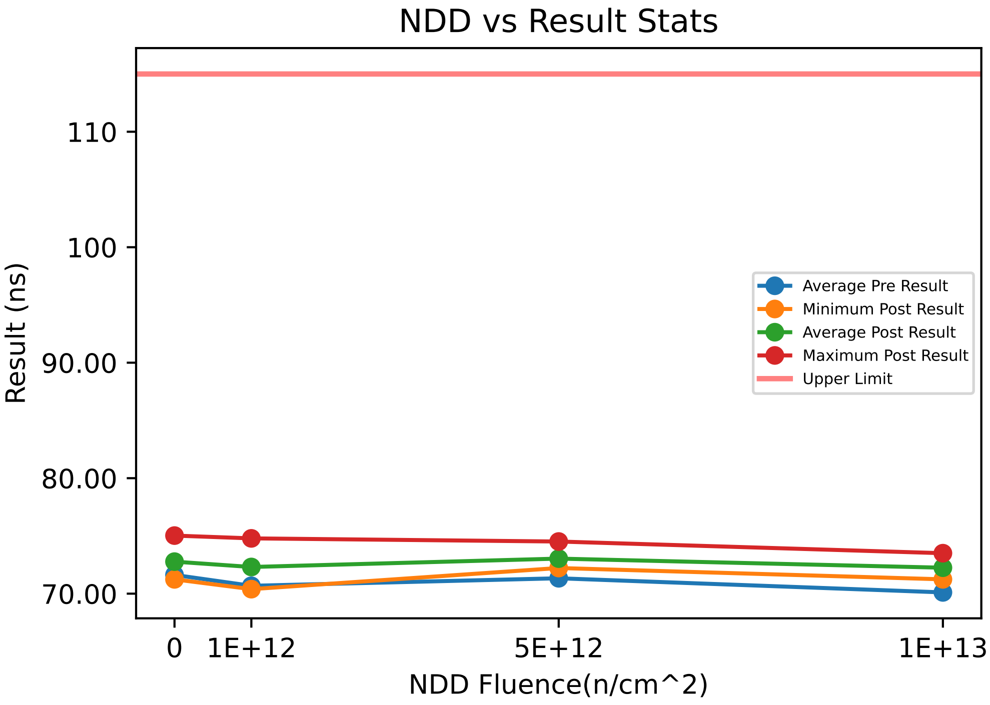
Test Results (Upper Limit = 115.0 (ns))

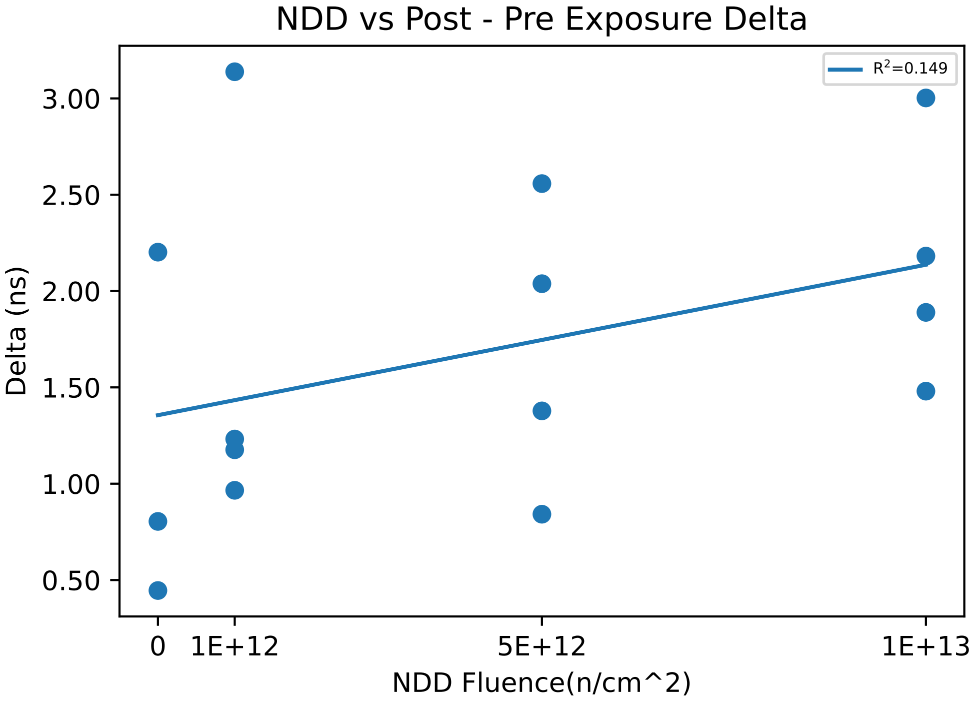
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	60.551	62.298	1.7464
2	1e+12	NDD	65.411	67.651	2.2405
3	1e+12	NDD	63.647	65.332	1.685
4	1e+12	NDD	61.292	62.219	0.9267
5	5e+12	NDD	64.273	65.646	1.3727
6	5e+12	NDD	62.43	63.749	1.3189
7	5e+12	NDD	63.783	64.87	1.0877
8	5e+12	NDD	64.461	65.974	1.5129
9	1e+13	NDD	62.944	63.956	1.0119
10	1e+13	NDD	62.901	63.222	0.3205
11	1e+13	NDD	65.009	65.502	0.493
12	1e+13	NDD	62.489	63.447	0.9581
13	0	CORRELATION	62.711	62.874	0.1625
14	0	CORRELATION	65.437	67.676	2.2392
15	0	CORRELATION	61.932	64.021	2.0888

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.932	63.36	65.437	1.8401	62.874	64.857	67.676	2.5078	0.1625	1.4968	2.2392	1.158
1e+12	60.551	62.725	65.411	2.2241	62.219	64.375	67.651	2.6212	0.9267	1.6497	2.2405	0.54233
5e+12	62.43	63.737	64.461	0.91699	63.749	65.06	65.974	0.98896	1.0877	1.3231	1.5129	0.17693
1e+13	62.489	63.336	65.009	1.1344	63.222	64.032	65.502	1.0274	0.3205	0.69588	1.0119	0.34191

Device Test: 28.33 TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/100kHz//@CS_ILIM_DELAY





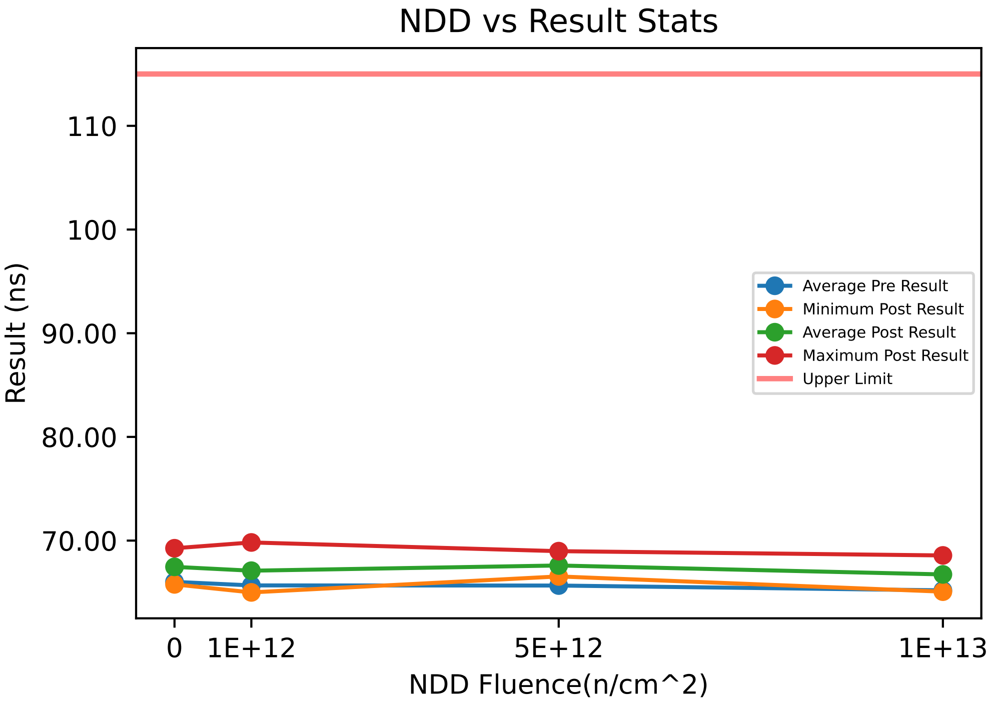
Test Results (Upper Limit = 115.0 (ns))

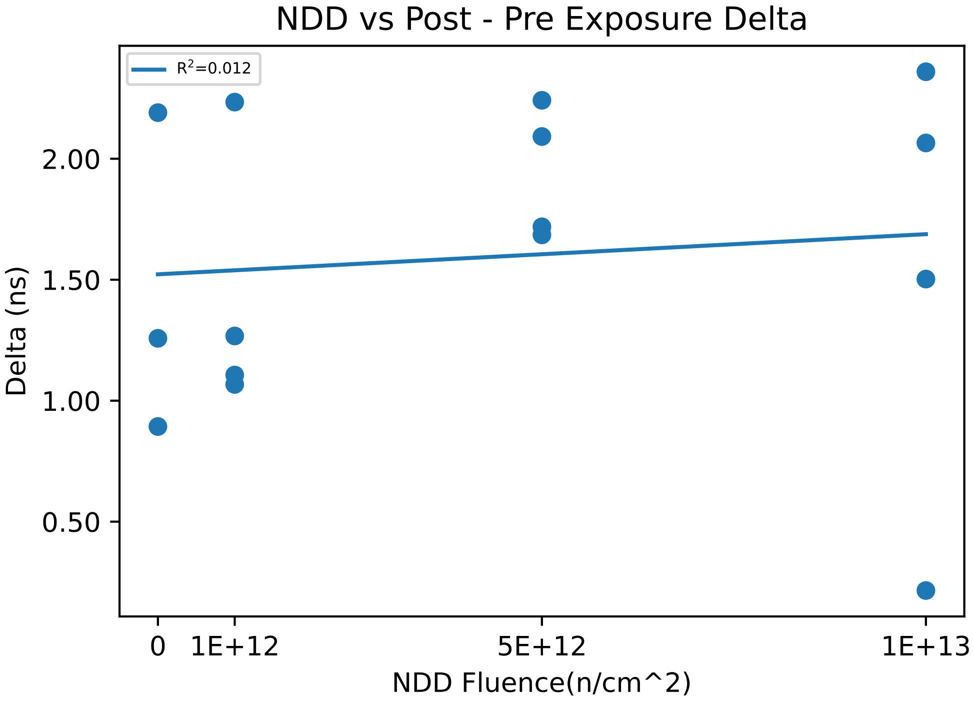
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	69.214	70.391	1.1762
2	1e+12	NDD	73.822	74.787	0.9658
3	1e+12	NDD	70.499	73.637	3.1384
4	1e+12	NDD	69.192	70.424	1.2319
5	5e+12	NDD	72.477	74.515	2.0382
6	5e+12	NDD	69.981	72.538	2.5578
7	5e+12	NDD	71.379	72.221	0.8417
8	5e+12	NDD	71.49	72.868	1.378
9	1e+13	NDD	69.673	71.855	2.1815
10	1e+13	NDD	69.351	71.241	1.8893
11	1e+13	NDD	72.024	73.504	1.4805
12	1e+13	NDD	69.389	72.391	3.0024
13	0	CORRELATION	70.434	71.238	0.8043
14	0	CORRELATION	74.583	75.028	0.4456
15	0	CORRELATION	69.849	72.051	2.202

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.849	71.622	74.583	2.581	71.238	72.772	75.028	1.9955	0.4456	1.1506	2.202	0.92801
1e+12	69.192	70.682	73.822	2.1807	70.391	72.31	74.787	2.2466	0.9658	1.6281	3.1384	1.0134
5e+12	69.981	71.332	72.477	1.0271	72.221	73.036	74.515	1.0211	0.8417	1.7039	2.5578	0.75067
1e+13	69.351	70.109	72.024	1.2843	71.241	72.248	73.504	0.96049	1.4805	2.1384	3.0024	0.64375

Device Test: 28.34 TIMING|DELAY/CS/5/5/0/1000/5/100kHz//@CS_ILIM_DELAY





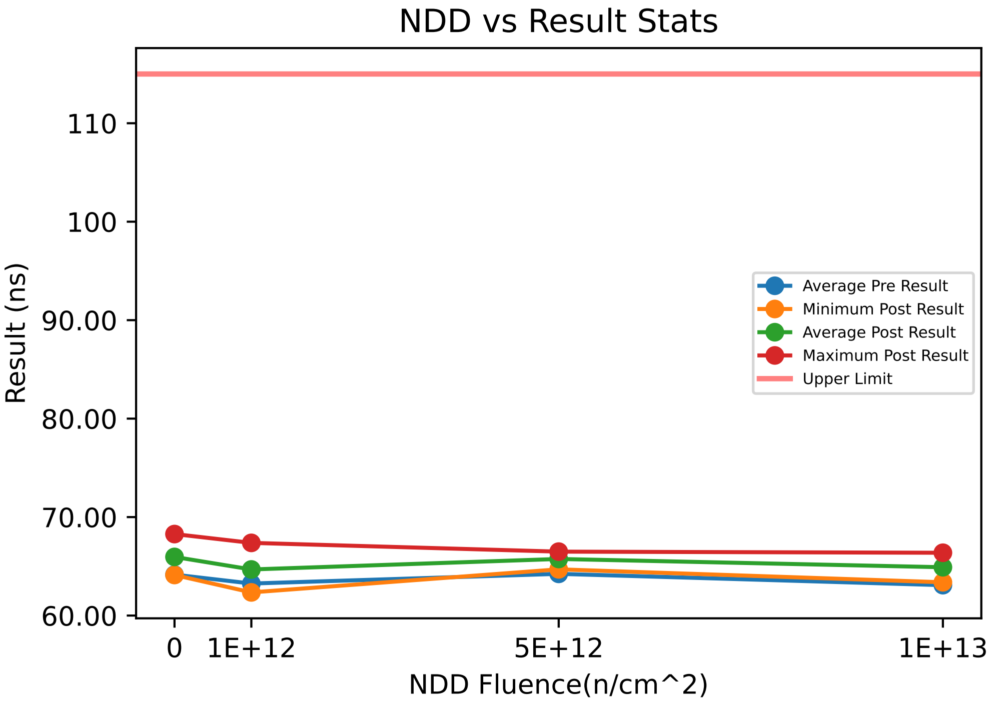
Test Results (Upper Limit = 115.0 (ns))

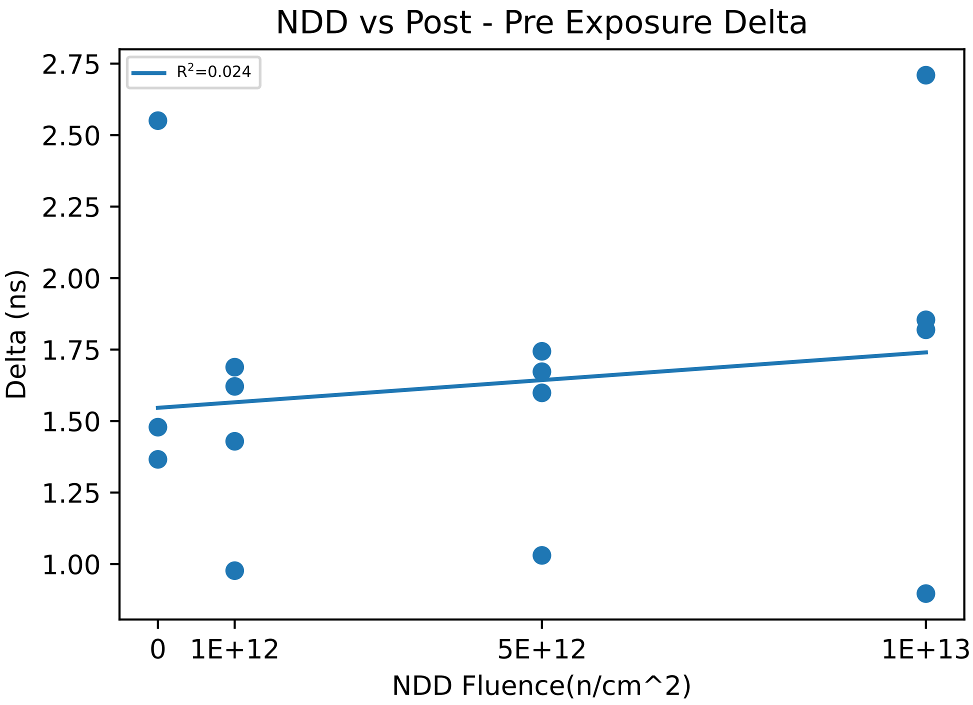
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	63.898	65.004	1.1061
2	1e+12	NDD	68.553	69.821	1.2675
3	1e+12	NDD	65.855	68.089	2.2341
4	1e+12	NDD	64.409	65.477	1.0673
5	5e+12	NDD	66.889	68.981	2.0919
6	5e+12	NDD	64.303	66.545	2.2416
7	5e+12	NDD	65.713	67.398	1.6854
8	5e+12	NDD	65.757	67.476	1.7186
9	1e+13	NDD	64.496	66.561	2.0653
10	1e+13	NDD	64.86	65.076	0.2154
11	1e+13	NDD	67.068	68.57	1.5027
12	1e+13	NDD	64.387	66.746	2.3596
13	0	CORRELATION	64.885	65.778	0.8933
14	0	CORRELATION	68.004	69.262	1.2578
15	0	CORRELATION	65.172	67.362	2.1906

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.885	66.02	68.004	1.724	65.778	67.467	69.262	1.7442	0.8933	1.4472	2.1906	0.66907
1e+12	63.898	65.679	68.553	2.0878	65.004	67.098	69.821	2.2663	1.0673	1.4187	2.2341	0.55044
5e+12	64.303	65.665	66.889	1.059	66.545	67.6	68.981	1.0128	1.6854	1.9344	2.2416	0.27553
1e+13	64.387	65.203	67.068	1.2598	65.076	66.738	68.57	1.4321	0.2154	1.5357	2.3596	0.94931

Device Test: 28.35 TIMING|DELAY/CS/12/12/0/1000/5/100kHz//@CS_ILIM_DELAY


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

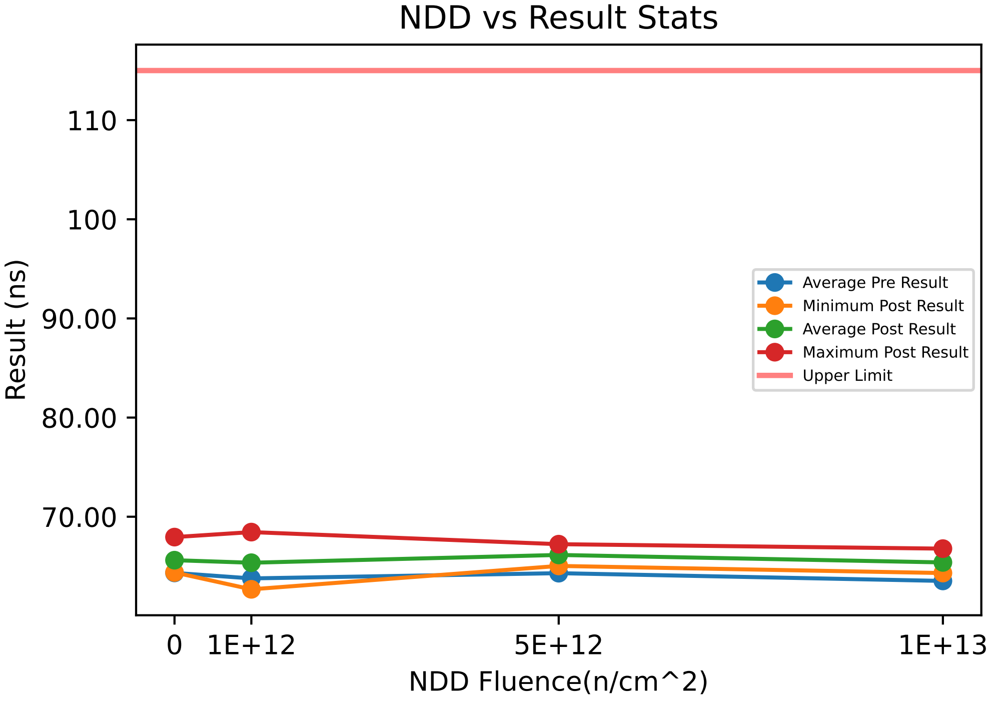
Test Results (Upper Limit = 115.0 (ns))

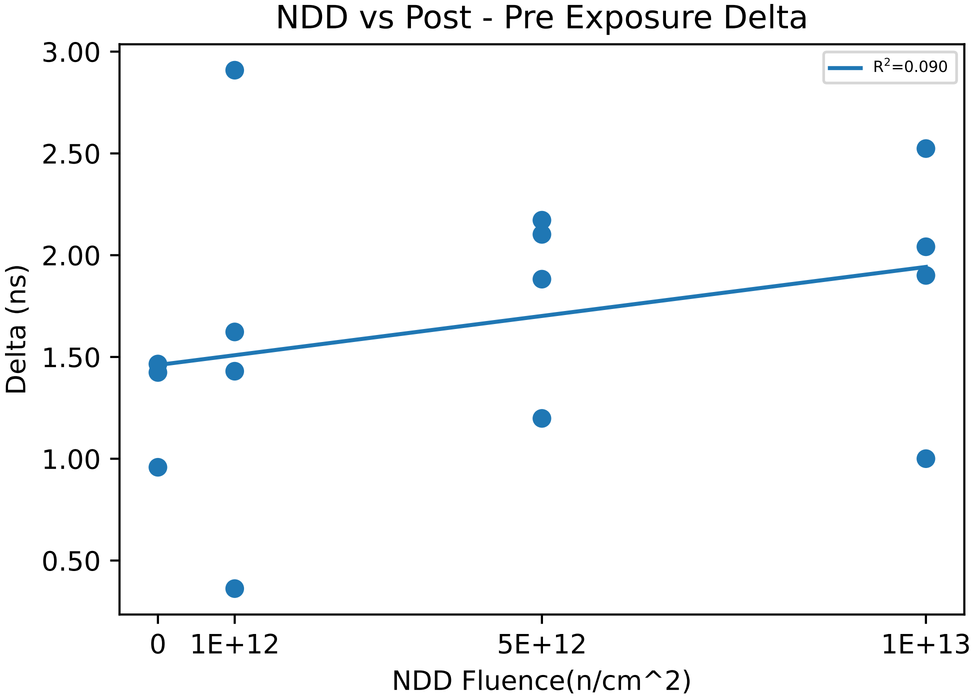
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.375	62.352	0.9769
2	1e+12	NDD	65.952	67.382	1.4293
3	1e+12	NDD	63.784	65.472	1.6885
4	1e+12	NDD	61.896	63.517	1.6213
5	5e+12	NDD	64.893	66.492	1.5987
6	5e+12	NDD	63.023	64.695	1.6726
7	5e+12	NDD	64.484	65.514	1.0303
8	5e+12	NDD	64.544	66.288	1.744
9	1e+13	NDD	62.769	65.478	2.7096
10	1e+13	NDD	62.484	63.381	0.8967
11	1e+13	NDD	64.558	66.378	1.8192
12	1e+13	NDD	62.539	64.394	1.8541
13	0	CORRELATION	62.753	64.12	1.3661
14	0	CORRELATION	66.798	68.276	1.4787
15	0	CORRELATION	62.916	65.466	2.5506

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.753	64.156	66.798	2.2897	64.12	65.954	68.276	2.121	1.3661	1.7985	2.5506	0.6538
1e+12	61.375	63.252	65.952	2.0766	62.352	64.681	67.382	2.2135	0.9769	1.429	1.6885	0.32079
5e+12	63.023	64.236	64.893	0.82878	64.695	65.747	66.492	0.81819	1.0303	1.5114	1.744	0.32617
1e+13	62.484	63.088	64.558	0.98826	63.381	64.908	66.378	1.3016	0.8967	1.8199	2.7096	0.7405

Device Test: 28.36 TIMING|DELAY/CS/14/14/0/1000/5/100kHz//@CS_ILIM_DELAY





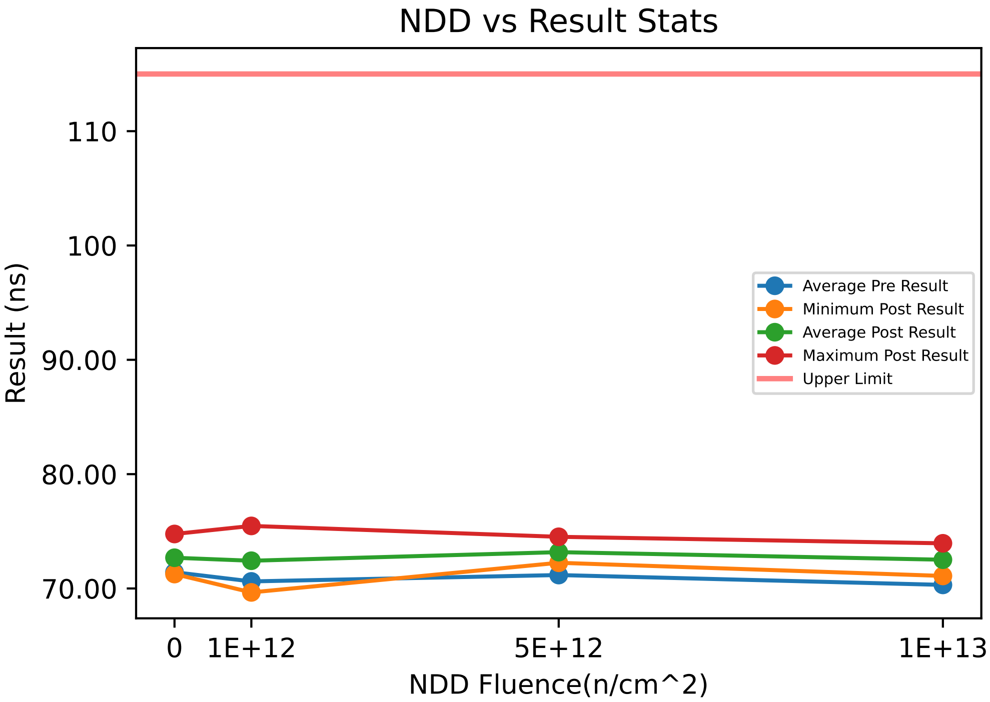
Test Results (Upper Limit = 115.0 (ns))

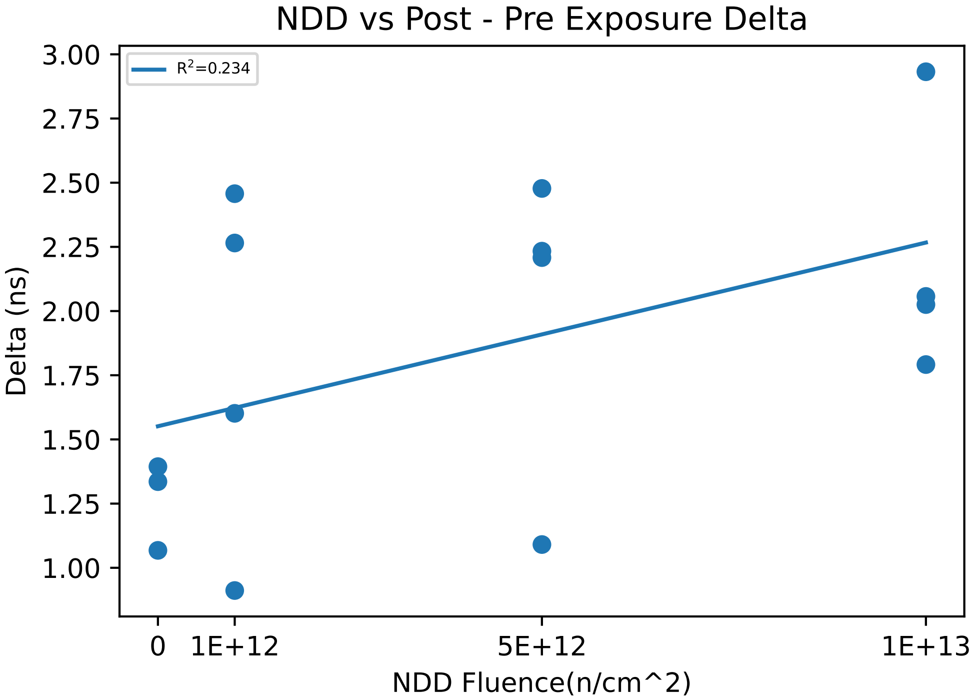
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	62.317	62.679	0.3621
2	1e+12	NDD	67.02	68.45	1.43
3	1e+12	NDD	63.508	66.417	2.9088
4	1e+12	NDD	62.273	63.896	1.623
5	5e+12	NDD	65.059	67.231	2.1719
6	5e+12	NDD	63.156	65.038	1.8822
7	5e+12	NDD	64.091	65.289	1.1982
8	5e+12	NDD	64.923	67.025	2.1022
9	1e+13	NDD	62.662	65.186	2.5238
10	1e+13	NDD	63.32	64.32	1.0004
11	1e+13	NDD	64.882	66.782	1.9006
12	1e+13	NDD	63.238	65.28	2.0414
13	0	CORRELATION	63.422	64.38	0.9581
14	0	CORRELATION	66.481	67.946	1.4654
15	0	CORRELATION	63.099	64.523	1.4238

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.099	64.334	66.481	1.866	64.38	65.616	67.946	2.0188	0.9581	1.2824	1.4654	0.28165
1e+12	62.273	63.78	67.02	2.2348	62.679	65.361	68.45	2.5818	0.3621	1.581	2.9088	1.0446
5e+12	63.156	64.307	65.059	0.87878	65.038	66.146	67.231	1.1419	1.1982	1.8386	2.1719	0.44444
1e+13	62.662	63.525	64.882	0.95046	64.32	65.392	66.782	1.0225	1.0004	1.8666	2.5238	0.63611

Device Test: 28.37 TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/500kHz//@CS_ILIM_DELAY





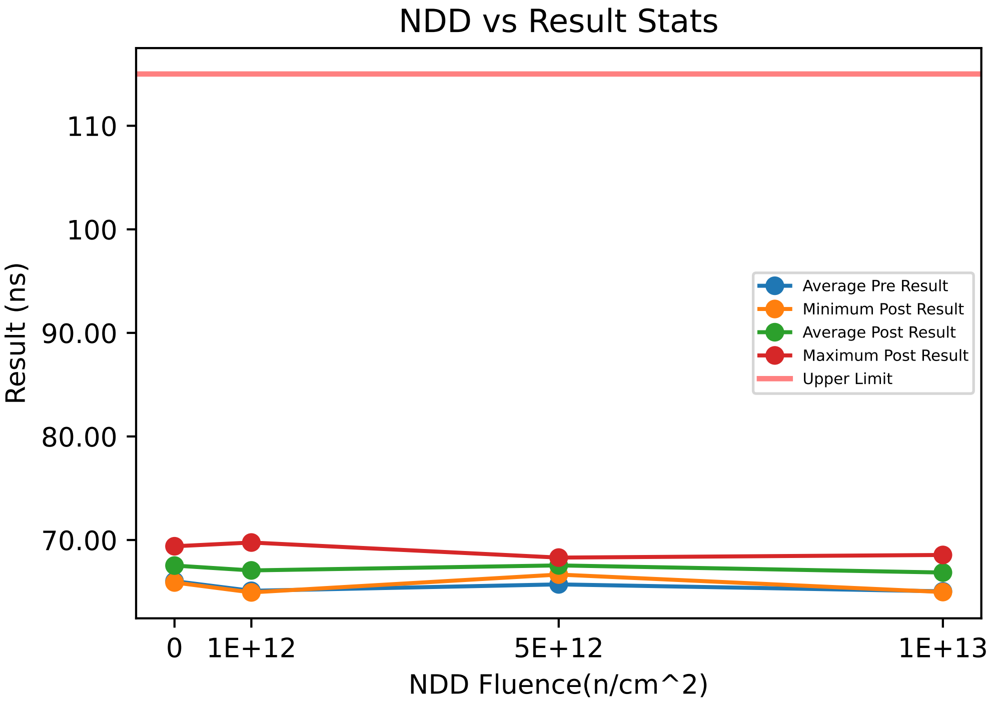
Test Results (Upper Limit = 115.0 (ns))

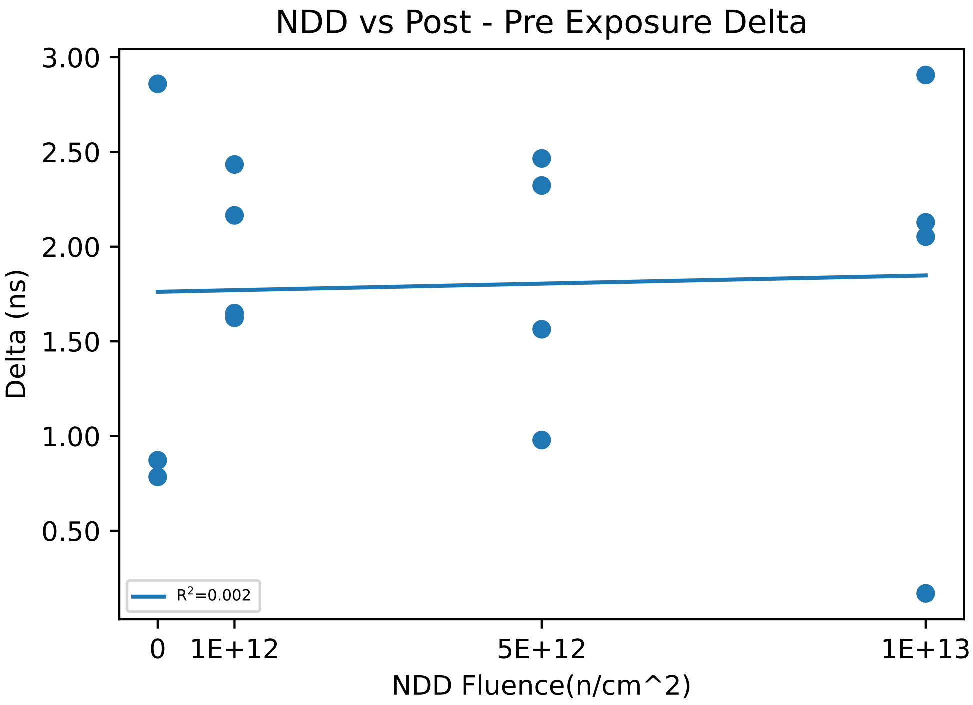
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	68.744	69.656	0.9115
2	1e+12	NDD	73.206	75.471	2.2651
3	1e+12	NDD	71.279	73.736	2.4572
4	1e+12	NDD	69.237	70.839	1.6016
5	5e+12	NDD	72.311	74.519	2.2083
6	5e+12	NDD	69.918	72.395	2.4776
7	5e+12	NDD	71.157	72.248	1.0906
8	5e+12	NDD	71.311	73.545	2.2333
9	1e+13	NDD	70.706	72.763	2.057
10	1e+13	NDD	69.305	71.097	1.7916
11	1e+13	NDD	71.924	73.949	2.0253
12	1e+13	NDD	69.32	72.252	2.9321
13	0	CORRELATION	69.867	71.261	1.394
14	0	CORRELATION	73.43	74.765	1.3356
15	0	CORRELATION	70.966	72.034	1.0679

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.867	71.421	73.43	1.8243	71.261	72.687	74.765	1.841	1.0679	1.2658	1.394	0.17388
1e+12	68.744	70.617	73.206	2.0455	69.656	72.426	75.471	2.6572	0.9115	1.8089	2.4572	0.7016
5e+12	69.918	71.174	72.311	0.98142	72.248	73.177	74.519	1.0664	1.0906	2.0024	2.4776	0.61992
1e+13	69.305	70.314	71.924	1.2584	71.097	72.515	73.949	1.183	1.7916	2.2015	2.9321	0.50124

Device Test: 28.38 TIMING|DELAY/CS/5/5/0/1000/5/500kHz//@CS_ILIM_DELAY





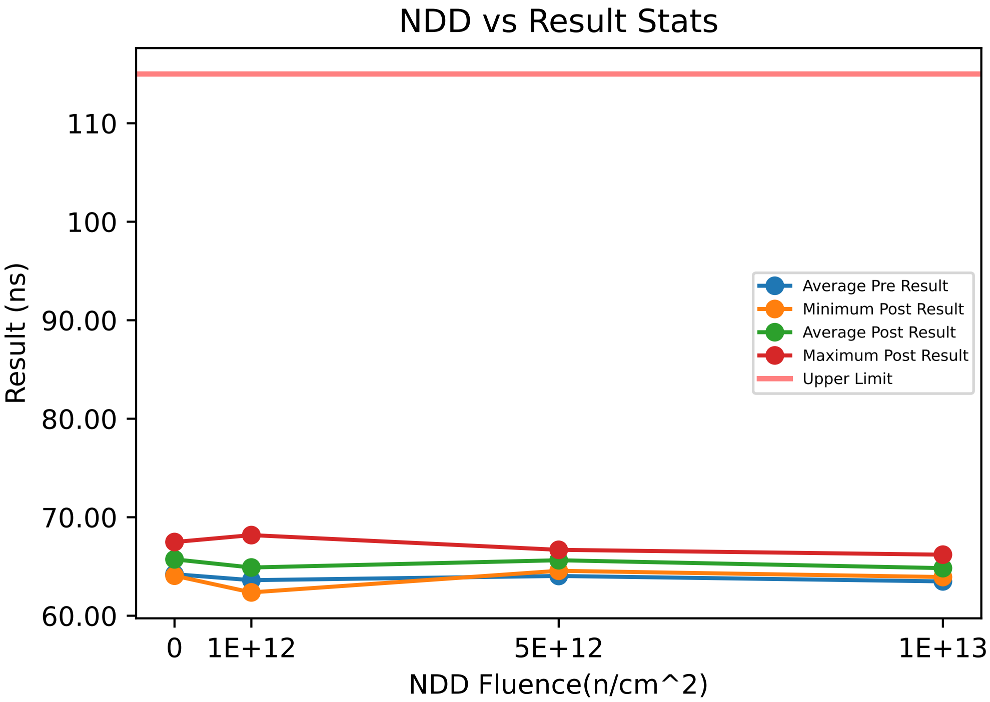
Test Results (Upper Limit = 115.0 (ns))

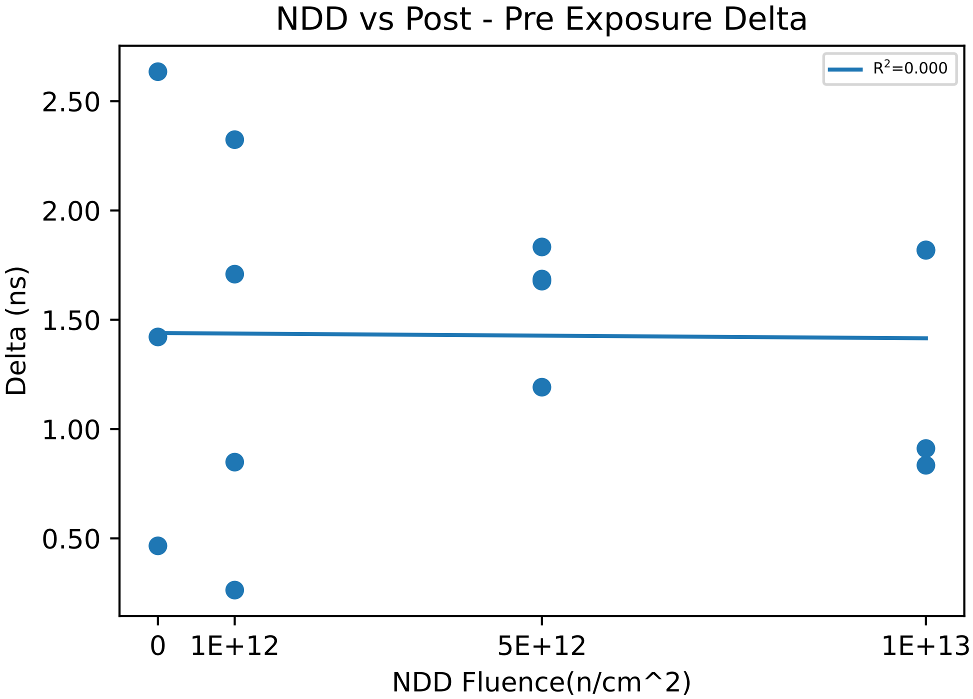
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	63.292	64.941	1.6493
2	1e+12	NDD	67.592	69.758	2.1654
3	1e+12	NDD	65.619	68.053	2.434
4	1e+12	NDD	63.879	65.503	1.6244
5	5e+12	NDD	66.738	68.302	1.564
6	5e+12	NDD	64.7	67.166	2.4657
7	5e+12	NDD	65.685	66.664	0.9789
8	5e+12	NDD	65.739	68.062	2.3229
9	1e+13	NDD	64.991	67.119	2.1283
10	1e+13	NDD	64.807	64.976	0.1694
11	1e+13	NDD	66.504	68.557	2.0528
12	1e+13	NDD	63.882	66.788	2.9065
13	0	CORRELATION	65.026	65.898	0.8721
14	0	CORRELATION	68.612	69.396	0.7844
15	0	CORRELATION	64.442	67.302	2.8596

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.442	66.027	68.612	2.2577	65.898	67.532	69.396	1.7602	0.7844	1.5054	2.8596	1.1736
1e+12	63.292	65.096	67.592	1.9358	64.941	67.064	69.758	2.2492	1.6244	1.9683	2.434	0.39823
5e+12	64.7	65.716	66.738	0.83207	66.664	67.548	68.302	0.76602	0.9789	1.8329	2.4657	0.69334
1e+13	63.882	65.046	66.504	1.0864	64.976	66.86	68.557	1.4719	0.1694	1.8142	2.9065	1.1625

Device Test: 28.39 TIMING|DELAY/CS/12/12/0/1000/5/500kHz//@CS_ILIM_DELAY





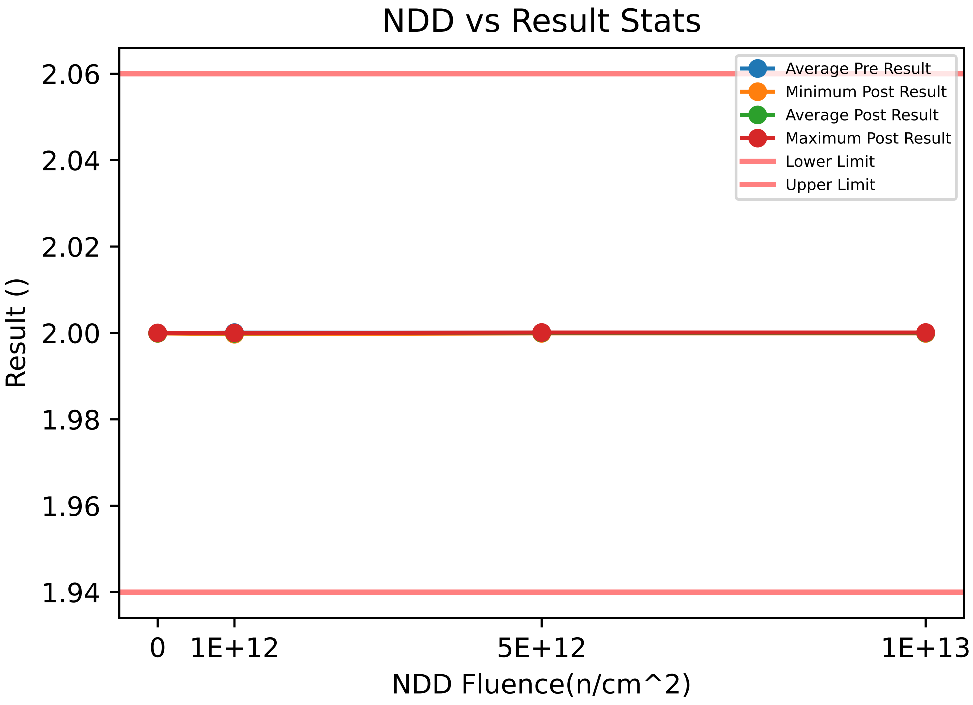
Test Results (Upper Limit = 115.0 (ns))

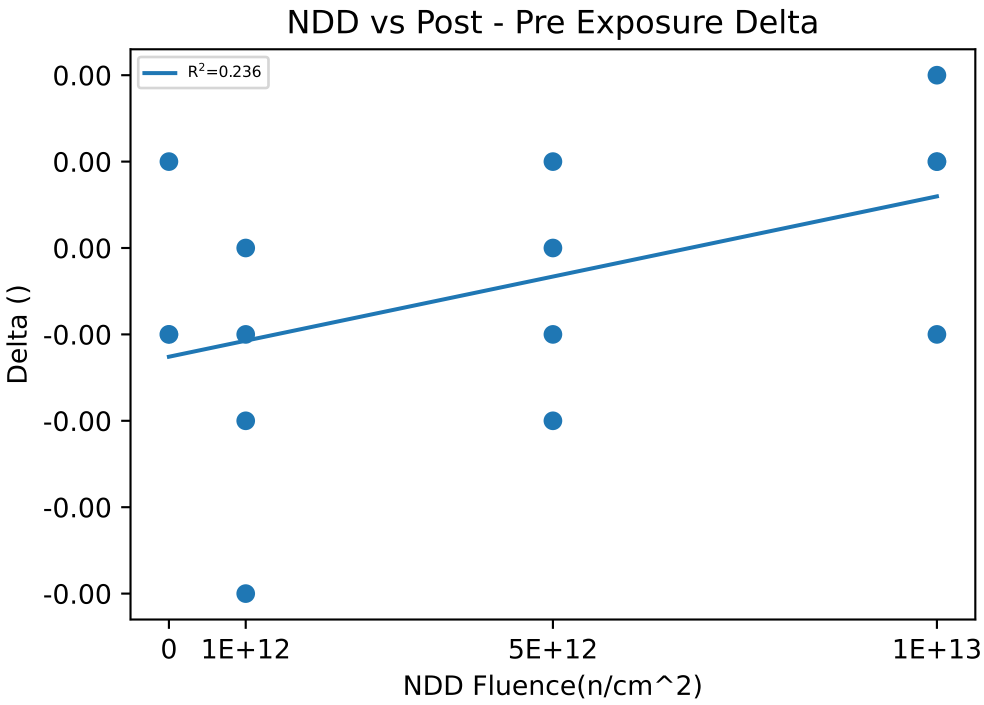
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.521	62.37	0.8487
2	1e+12	NDD	66.478	68.186	1.7087
3	1e+12	NDD	63.804	66.129	2.324
4	1e+12	NDD	62.642	62.905	0.2633
5	5e+12	NDD	64.564	66.397	1.8331
6	5e+12	NDD	62.887	64.564	1.6767
7	5e+12	NDD	63.692	64.884	1.1916
8	5e+12	NDD	65.005	66.692	1.6863
9	1e+13	NDD	63.007	64.827	1.8198
10	1e+13	NDD	63.094	63.928	0.8343
11	1e+13	NDD	65.289	66.2	0.9111
12	1e+13	NDD	62.558	64.376	1.8175
13	0	CORRELATION	62.644	64.066	1.4214
14	0	CORRELATION	67.017	67.483	0.4657
15	0	CORRELATION	62.995	65.629	2.6349

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.644	64.219	67.017	2.4297	64.066	65.726	67.483	1.7105	0.4657	1.5073	2.6349	1.0872
1e+12	61.521	63.611	66.478	2.1262	62.37	64.897	68.186	2.7502	0.2633	1.2862	2.324	0.91164
5e+12	62.887	64.037	65.005	0.94111	64.564	65.634	66.692	1.0661	1.1916	1.5969	1.8331	0.27953
1e+13	62.558	63.487	65.289	1.2237	63.928	64.833	66.2	0.98235	0.8343	1.3457	1.8198	0.54704

Device Test: 28.4 LEVEL|RATIO/CS/14/14/0/0/5/500kHz//@C_CS_R





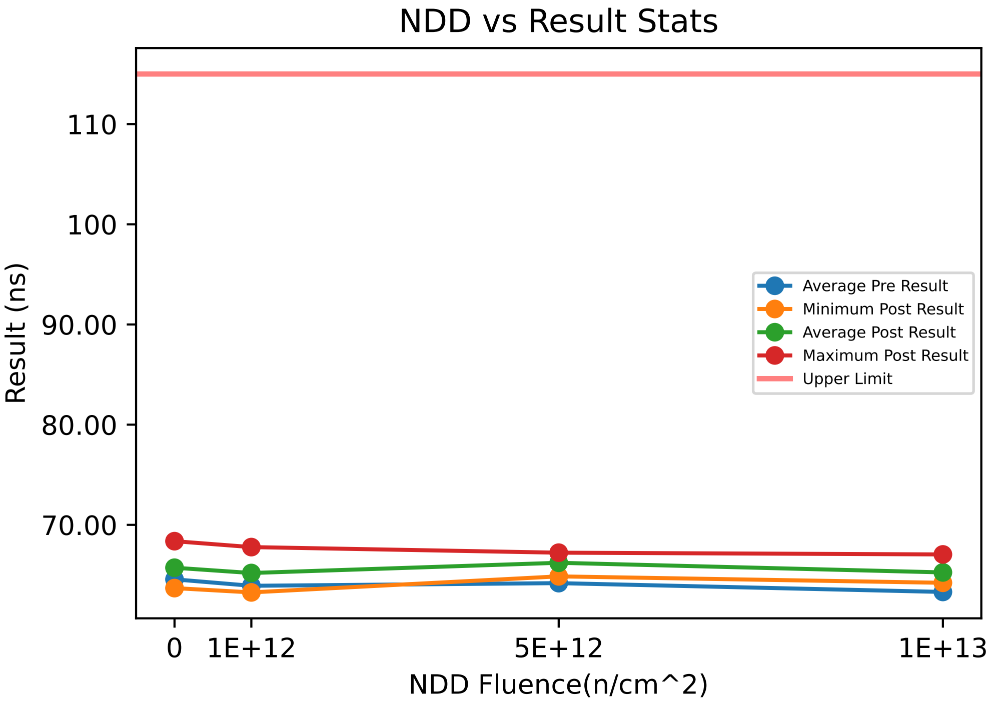
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

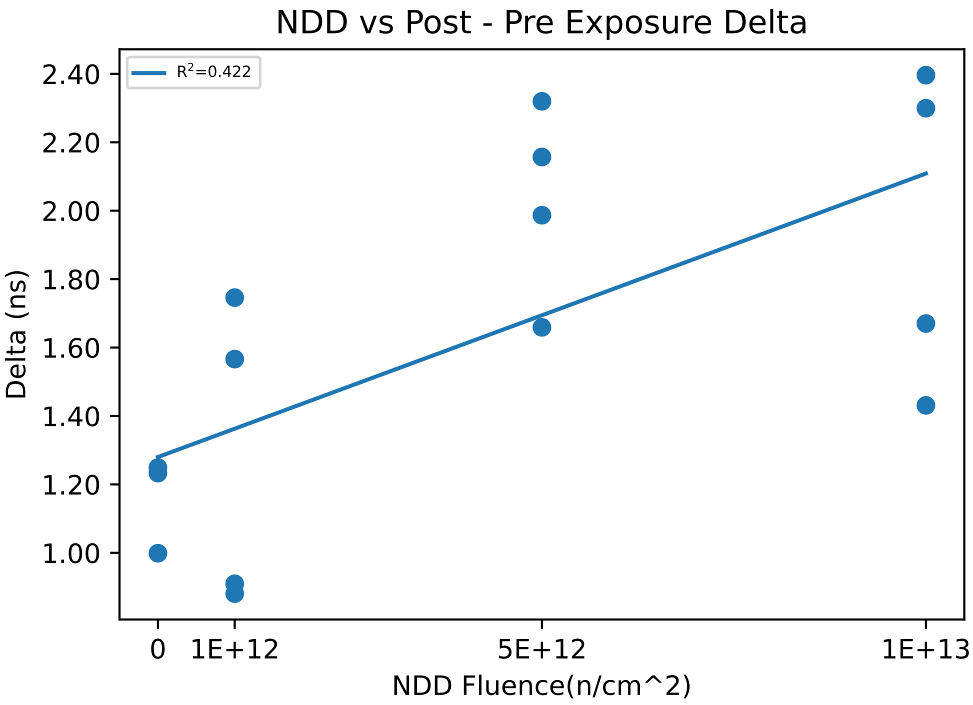
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	2	2	0
2	1e+12	NDD	2.0001	1.9999	-0.0002
3	1e+12	NDD	2.0001	1.9997	-0.0004
4	1e+12	NDD	2.0001	2	-0.0001
5	5e+12	NDD	2	2	0
6	5e+12	NDD	2.0001	1.9999	-0.0002
7	5e+12	NDD	2	2.0001	0.0001
8	5e+12	NDD	2.0001	2	-0.0001
9	1e+13	NDD	1.9998	2	0.0002
10	1e+13	NDD	1.9998	1.9999	0.0001
11	1e+13	NDD	1.9999	2	0.0001
12	1e+13	NDD	2.0002	2.0001	-0.0001
13	0	CORRELATION	2	1.9999	-0.0001
14	0	CORRELATION	2	1.9999	-0.0001
15	0	CORRELATION	1.9999	2	0.0001

Test Statistics ()

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2	5.7735e-05	1.9999	1.9999	2	5.7735e-05	-0.0001	-3.3333e-05	0.0001	0.00011547
1e+12	2	2.0001	2.0001	5e-05	1.9997	1.9999	2	0.00014142	-0.0004	-0.000175	0	0.00017078
5e+12	2	2	2.0001	5.7735e-05	1.9999	2	2.0001	8.165e-05	-0.0002	-5e-05	0.0001	0.0001291
1e+13	1.9998	1.9999	2.0002	0.0001893	1.9999	2	2.0001	8.165e-05	-0.0001	7.5e-05	0.0002	0.00012583

Device Test: 28.40 TIMING|DELAY/CS/14/14/0/1000/5/500kHz//@CS_ILIM_DELAY





Test Results (Upper Limit = 115.0 (ns))

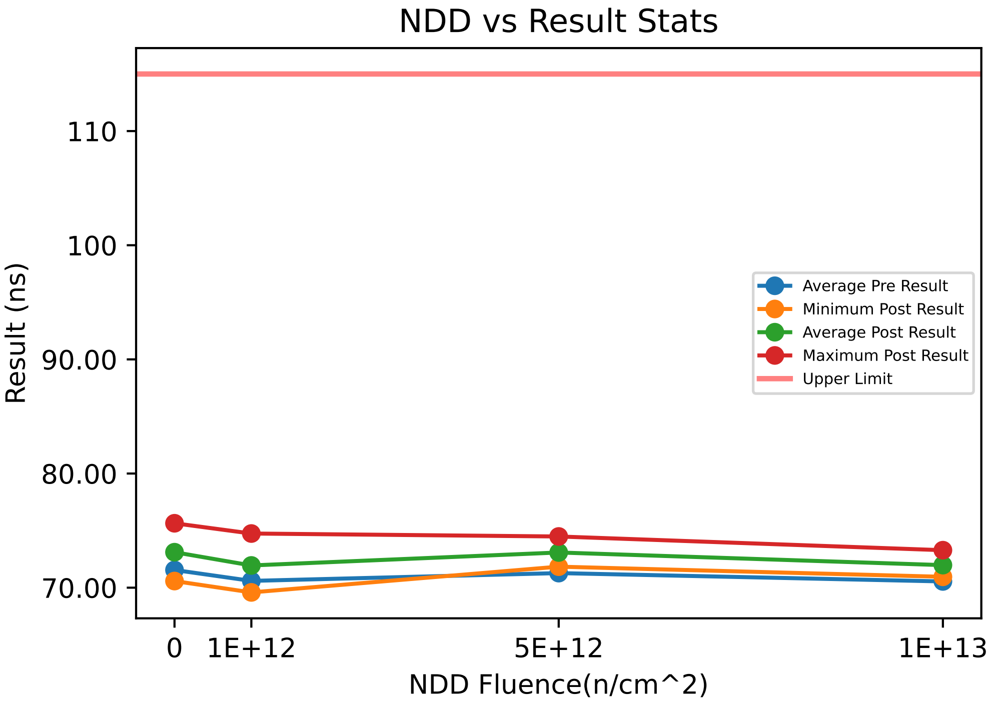
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.693	63.259	1.5662
2	1e+12	NDD	66.901	67.781	0.8808
3	1e+12	NDD	64.174	65.92	1.746
4	1e+12	NDD	62.909	63.819	0.9095
5	5e+12	NDD	65.066	67.223	2.157
6	5e+12	NDD	62.539	64.859	2.3198
7	5e+12	NDD	64.163	65.823	1.6591
8	5e+12	NDD	64.969	66.955	1.9868
9	1e+13	NDD	62.803	65.103	2.2996
10	1e+13	NDD	62.787	64.218	1.431
11	1e+13	NDD	65.379	67.049	1.6702
12	1e+13	NDD	62.252	64.648	2.3961
13	0	CORRELATION	62.69	63.688	0.9988
14	0	CORRELATION	67.138	68.372	1.2331
15	0	CORRELATION	63.858	65.107	1.2491

Test Statistics (ns)

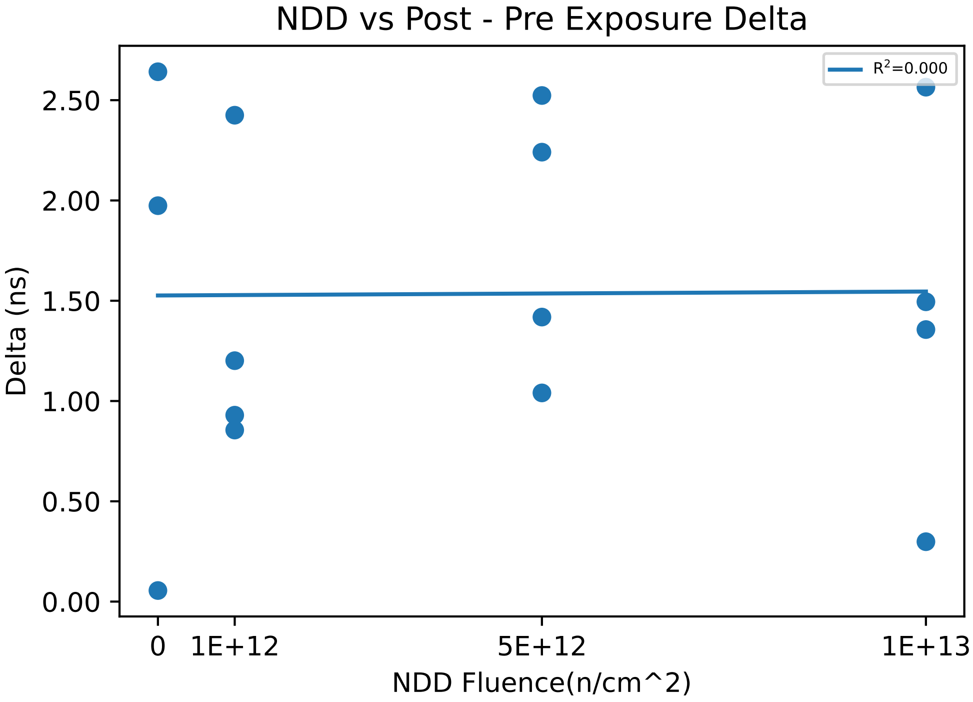
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.69	64.562	67.138	2.3065	63.688	65.722	68.372	2.4015	0.9988	1.1603	1.2491	0.14012
1e+12	61.693	63.919	66.901	2.2308	63.259	65.195	67.781	2.0702	0.8808	1.2756	1.746	0.44558
5e+12	62.539	64.184	65.066	1.169	64.859	66.215	67.223	1.089	1.6591	2.0307	2.3198	0.28257
1e+13	62.252	63.305	65.379	1.4059	64.218	65.254	67.049	1.2497	1.431	1.9492	2.3961	0.47218

Device Test: 28.41 TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/1MHz//@CS_ILIM_DELAY

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



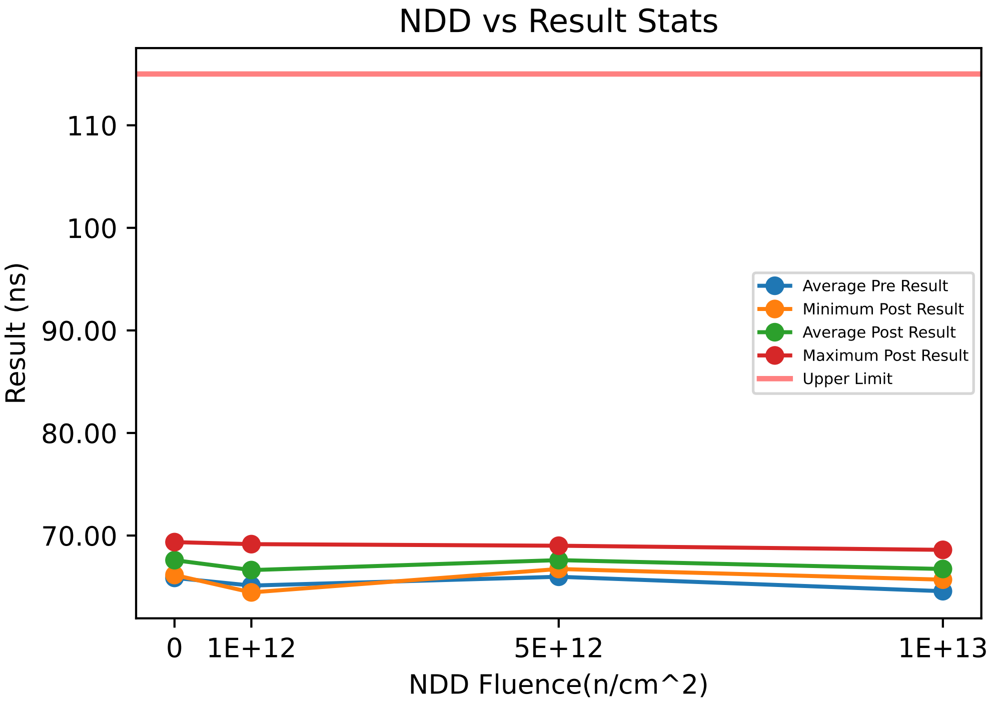
Test Results (Upper Limit = 115.0 (ns))

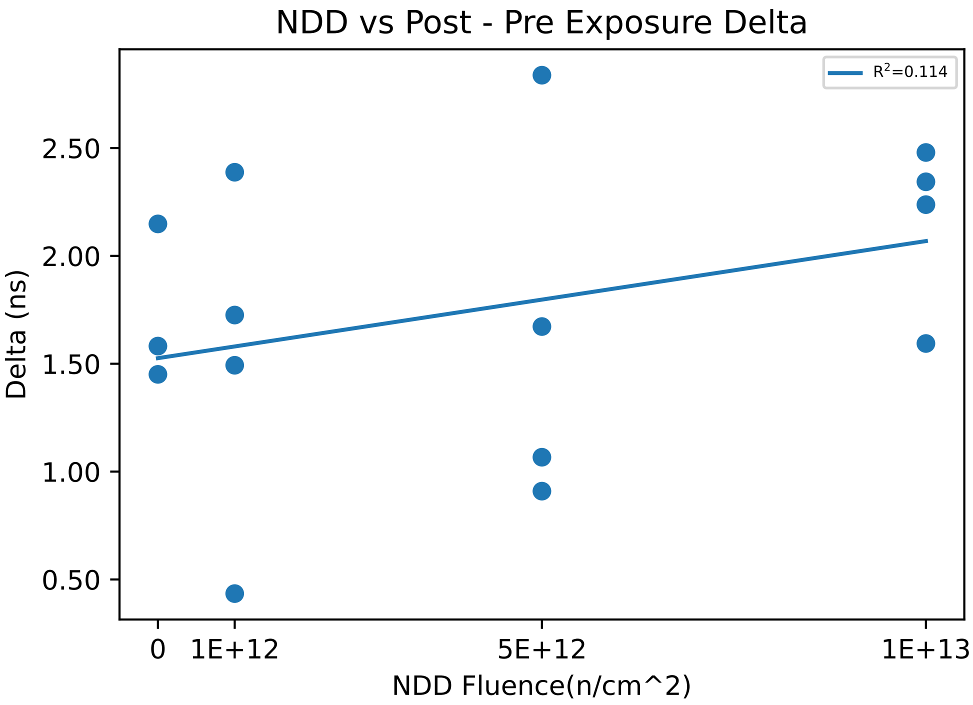
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	68.731	69.587	0.8553
2	1e+12	NDD	73.815	74.744	0.9294
3	1e+12	NDD	70.656	73.081	2.425
4	1e+12	NDD	69.177	70.378	1.2012
5	5e+12	NDD	73.067	74.486	1.4186
6	5e+12	NDD	69.601	71.841	2.2408
7	5e+12	NDD	71.189	72.229	1.0404
8	5e+12	NDD	71.254	73.777	2.5233
9	1e+13	NDD	69.526	72.091	2.5648
10	1e+13	NDD	69.458	70.953	1.4948
11	1e+13	NDD	72.985	73.284	0.2986
12	1e+13	NDD	70.22	71.577	1.3563
13	0	CORRELATION	70.525	70.581	0.0552
14	0	CORRELATION	73.668	75.642	1.974
15	0	CORRELATION	70.458	73.1	2.6417

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.458	71.551	73.668	1.8343	70.581	73.108	75.642	2.5309	0.0552	1.557	2.6417	1.3427
1e+12	68.731	70.595	73.815	2.2989	69.587	71.947	74.744	2.3904	0.8553	1.3527	2.425	0.73015
5e+12	69.601	71.278	73.067	1.4168	71.841	73.083	74.486	1.2542	1.0404	1.8058	2.5233	0.69277
1e+13	69.458	70.548	72.985	1.6611	70.953	71.976	73.284	0.98816	0.2986	1.4286	2.5648	0.92691

Device Test: 28.42 TIMING|DELAY/CS/5/5/0/1000/5/1MHz//@CS_ILIM_DELAY





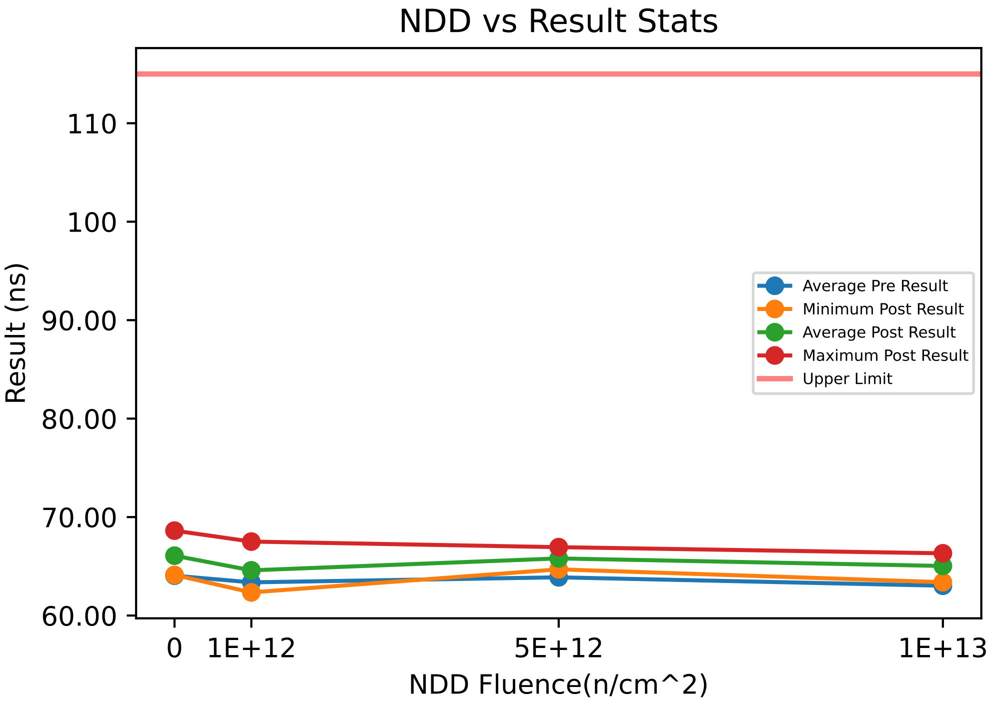
Test Results (Upper Limit = 115.0 (ns))

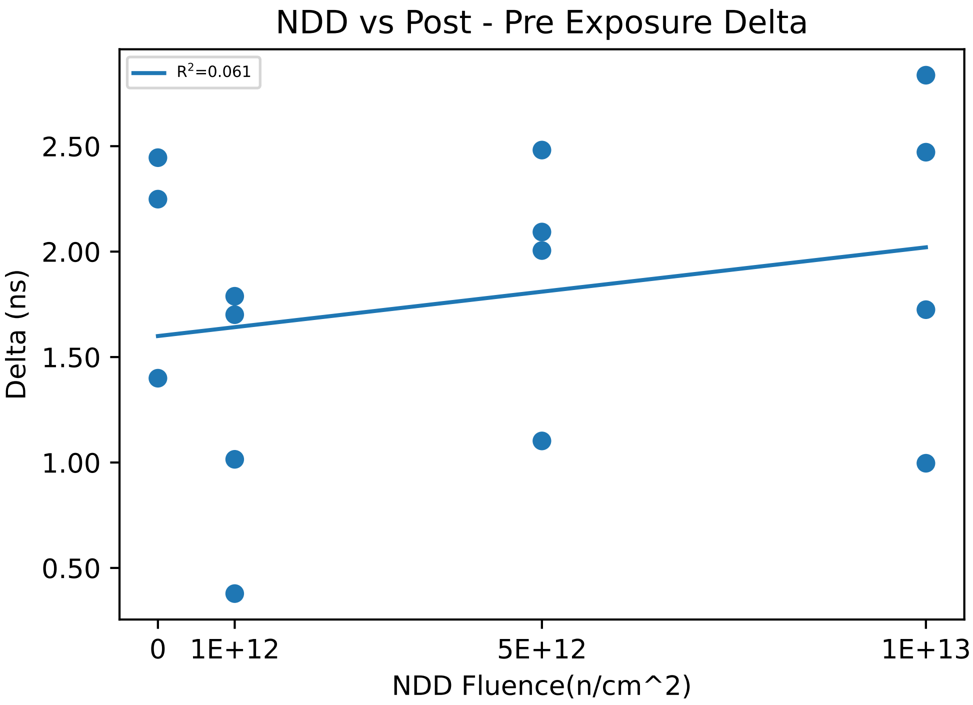
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	64.023	64.457	0.4345
2	1e+12	NDD	67.436	69.162	1.7258
3	1e+12	NDD	65.071	67.459	2.3878
4	1e+12	NDD	63.961	65.454	1.493
5	5e+12	NDD	67.336	69.009	1.6725
6	5e+12	NDD	64.27	67.108	2.8377
7	5e+12	NDD	65.674	66.74	1.0667
8	5e+12	NDD	66.649	67.559	0.9094
9	1e+13	NDD	64.255	66.492	2.2376
10	1e+13	NDD	64.106	65.7	1.5939
11	1e+13	NDD	66.263	68.606	2.3435
12	1e+13	NDD	63.679	66.159	2.4794
13	0	CORRELATION	64.572	66.154	1.5819
14	0	CORRELATION	67.909	69.36	1.4508
15	0	CORRELATION	65.138	67.286	2.1483

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.572	65.873	67.909	1.7859	66.154	67.6	69.36	1.6259	1.4508	1.727	2.1483	0.3707
1e+12	63.961	65.123	67.436	1.6243	64.457	66.633	69.162	2.0977	0.4345	1.5103	2.3878	0.81119
5e+12	64.27	65.982	67.336	1.3297	66.74	67.604	69.009	0.99456	0.9094	1.6216	2.8377	0.87495
1e+13	63.679	64.576	66.263	1.1507	65.7	66.739	68.606	1.2862	1.5939	2.1636	2.4794	0.39248

Device Test: 28.43 TIMING|DELAY/CS/12/12/0/1000/5/1MHz//@CS_ILIM_DELAY





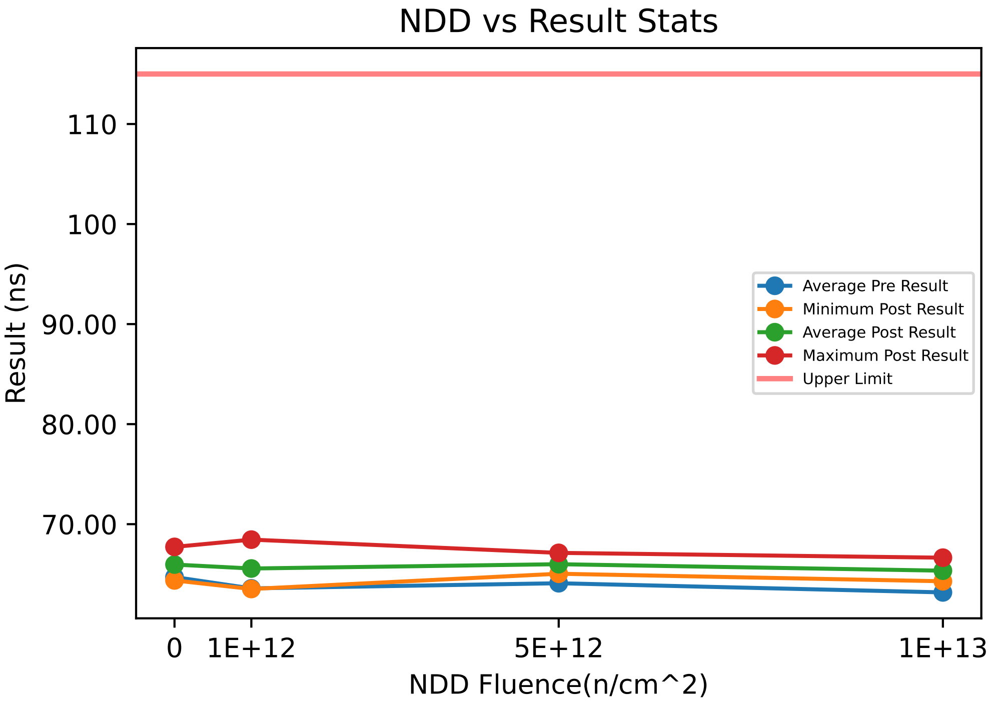
Test Results (Upper Limit = 115.0 (ns))

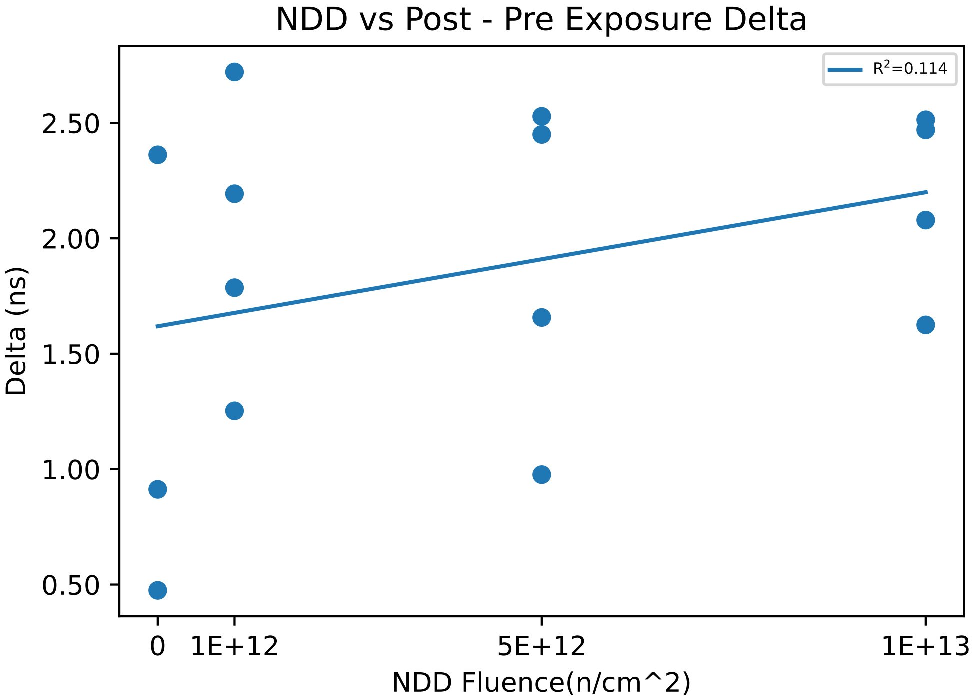
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.971	62.35	0.3784
2	1e+12	NDD	65.723	67.512	1.7883
3	1e+12	NDD	63.874	65.575	1.7009
4	1e+12	NDD	61.911	62.926	1.0151
5	5e+12	NDD	64.852	66.945	2.0929
6	5e+12	NDD	62.21	64.692	2.4815
7	5e+12	NDD	63.836	64.938	1.1023
8	5e+12	NDD	64.624	66.629	2.0051
9	1e+13	NDD	62.595	65.431	2.8365
10	1e+13	NDD	62.39	63.386	0.9965
11	1e+13	NDD	64.595	66.319	1.7247
12	1e+13	NDD	62.532	65.004	2.4714
13	0	CORRELATION	62.721	64.121	1.3997
14	0	CORRELATION	66.177	68.622	2.4454
15	0	CORRELATION	63.246	65.495	2.2488

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.721	64.048	66.177	1.8618	64.121	66.079	68.622	2.3065	1.3997	2.0313	2.4454	0.55574
1e+12	61.911	63.37	65.723	1.8145	62.35	64.591	67.512	2.401	0.3784	1.2207	1.7883	0.65942
5e+12	62.21	63.88	64.852	1.1955	64.692	65.801	66.945	1.1502	1.1023	1.9205	2.4815	0.5834
1e+13	62.39	63.028	64.595	1.048	63.386	65.035	66.319	1.2283	0.9965	2.0073	2.8365	0.81742

Device Test: 28.44 TIMING|DELAY/CS/14/14/0/1000/5/1MHz//@CS_ILIM_DELAY


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

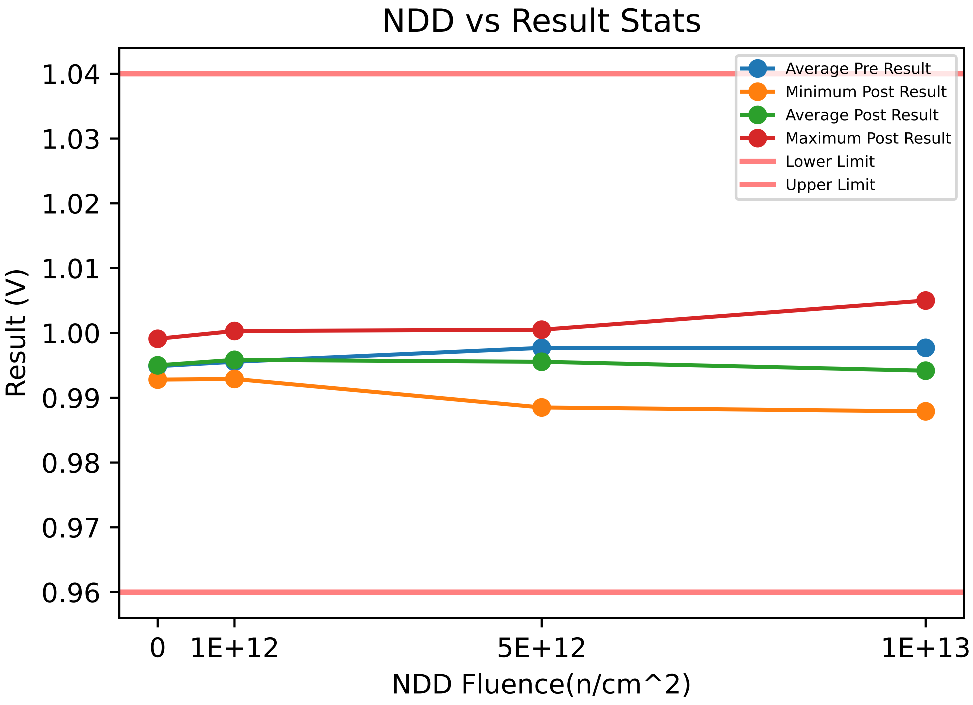
Test Results (Upper Limit = 115.0 (ns))

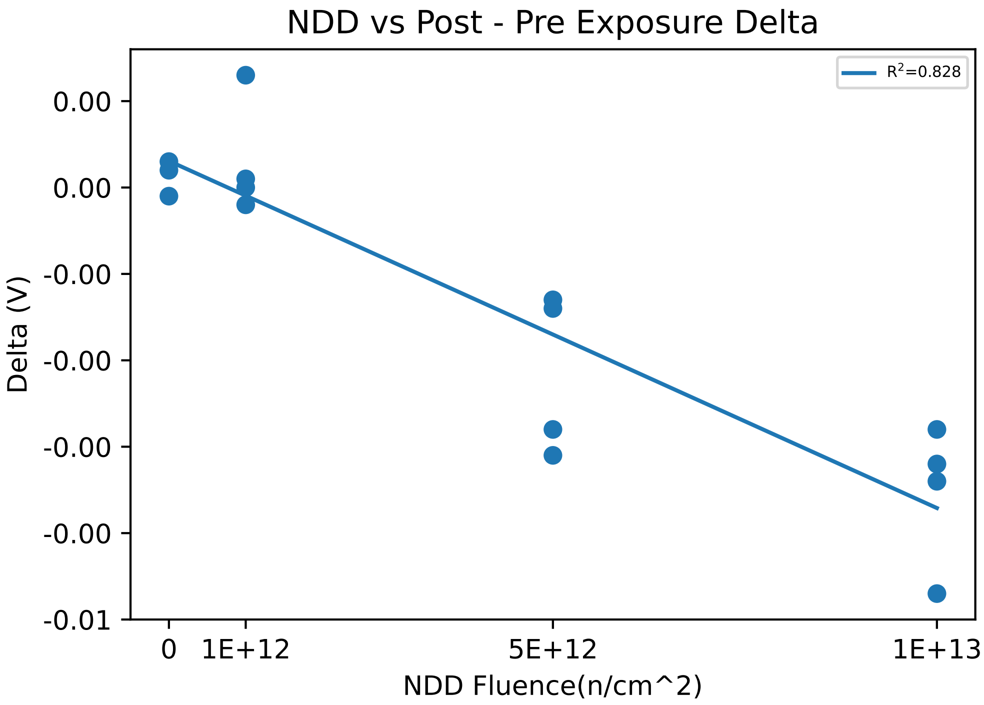
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	61.735	63.521	1.7861
2	1e+12	NDD	66.261	68.454	2.1932
3	1e+12	NDD	63.681	66.401	2.7208
4	1e+12	NDD	62.645	63.897	1.2526
5	5e+12	NDD	64.918	66.575	1.6571
6	5e+12	NDD	62.595	65.045	2.45
7	5e+12	NDD	64.266	65.242	0.9762
8	5e+12	NDD	64.602	67.13	2.5284
9	1e+13	NDD	62.587	65.057	2.4698
10	1e+13	NDD	62.667	64.292	1.6249
11	1e+13	NDD	64.57	66.649	2.0791
12	1e+13	NDD	62.892	65.406	2.5135
13	0	CORRELATION	63.465	64.378	0.9125
14	0	CORRELATION	67.253	67.728	0.4748
15	0	CORRELATION	63.419	65.781	2.3618

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.419	64.712	67.253	2.2004	64.378	65.962	67.728	1.6824	0.4748	1.2497	2.3618	0.98766
1e+12	61.735	63.58	66.261	1.956	63.521	65.568	68.454	2.3099	1.2526	1.9882	2.7208	0.62201
5e+12	62.595	64.095	64.918	1.035	65.045	65.998	67.13	1.0157	0.9762	1.9029	2.5284	0.73252
1e+13	62.587	63.179	64.57	0.93602	64.292	65.351	66.649	0.98244	1.6249	2.1718	2.5135	0.41362

Device Test: 28.9 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/100kHz//@V_CS_ILIM_OC


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	1e+12	NDD	1.0005	1.0003	-0.0002
2	1e+12	NDD	0.9945	0.9958	0.0013
3	1e+12	NDD	0.9928	0.9929	0.0001
4	1e+12	NDD	0.9944	0.9944	0
5	5e+12	NDD	1.0019	1.0005	-0.0014
6	5e+12	NDD	1.0033	1.0002	-0.0031
7	5e+12	NDD	0.9898	0.9885	-0.0013
8	5e+12	NDD	0.9958	0.993	-0.0028
9	1e+13	NDD	0.9944	0.9897	-0.0047
10	1e+13	NDD	1.0078	1.005	-0.0028
11	1e+13	NDD	0.9973	0.9941	-0.0032
12	1e+13	NDD	0.9913	0.9879	-0.0034
13	0	CORRELATION	0.9929	0.9931	0.0002
14	0	CORRELATION	0.9988	0.9991	0.0003
15	0	CORRELATION	0.9929	0.9928	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9929	0.99487	0.9988	0.0034064	0.9928	0.995	0.9991	0.0035539	-0.0001	0.00013333	0.0003	0.00020817
1e+12	0.9928	0.99555	1.0005	0.0033907	0.9929	0.99585	1.0003	0.0031943	-0.0002	0.0003	0.0013	0.00067823
5e+12	0.9898	0.9977	1.0033	0.0061919	0.9885	0.99555	1.0005	0.0058404	-0.0031	-0.00215	-0.0013	0.00093274
1e+13	0.9913	0.9977	1.0078	0.0071652	0.9879	0.99418	1.005	0.0076722	-0.0047	-0.003525	-0.0028	0.00082209

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